Reliability Report

TPS7H6005-SEP Neutron Displacement Damage (NDD) Characterization Report

ABSTRACT

This report presents the effect of neutron displacement damage (NDD) on the Texas Instruments TPS7H6005-SEP. The TPS7H6005-SEP showed a strong degree of hardness to neutron irradiation up to fluence level 1 × 10^{13} n/cm^{2}.

The neutron irradiation test is a destructive test. Test procedure follows MIL-STD-883 method 1017 as guidance. The purpose of this test is to determine the device susceptibility to non-ionizing energy loss (NIEL) degradation. Objectives of the test are, to detect and measure the degradation of critical device parameters as a function of neutron fluence and to determine if these parameters are within specified limits after exposure to a specified level of neutron fluence.

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Trademarks

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1 Device Information

1.1 Product Description

The TPS7H6005-SEP is a 200V radiation-hardness-assured, high-voltage gate driver for space applications. The TPS7H6005-SEP is designed for high-frequency, high-efficiency applications. The driver features adjustable dead time capability, small 30ns propagation delay and 5.5ns high-side and low-side matching. This part also includes internal high-side and low-side LDOs which specifies a drive voltage of 5V regardless of supply voltage. The TPS7H6005-SEP is packaged in a plastic 56-pin HTSSOP DCA package.

1.2 Device Details

Device and Exposure Details lists the device information used in the initial NDD characterization.

Table 1-1. Device and Exposure Details

NDD Exposure Details	
TI Device	TPS7H6005-SEP
TI Part Name	TPS7H6005MDCATSEP
Package	56-pin HTSSOP (DCA)
Technology	Linear BiCMOS (LBC7)
Assembly Lot Number / LTC	4365694ML4 / 46A8G2K
Quantity Tested	12 units + 2 correlation units
Exposure Facility	Fast Neutron Irradiation (FNI) Facility of University of Massachusetts Lowell Research Reactor (UMLRR)
Neutron Fluence (1-MeV equivalent) Level	1 × 10^{12}, 5 × 10^{12}, 1 × 10^{13} n/cm^2
Irradiation Temperature	Ambient room temperature (25ºC)

Figure 1-1. Device Used in Exposure (Front)

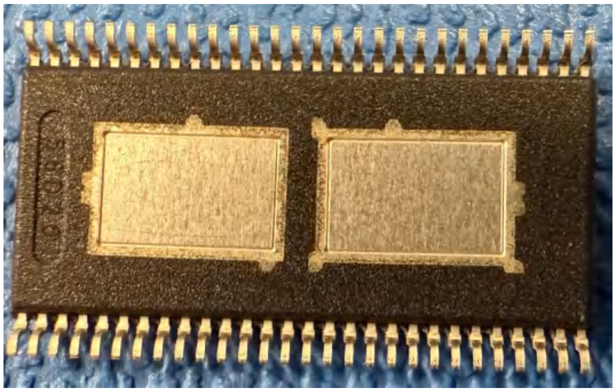


Figure 1-2. Device Used in Exposure (Back)

2 Total Dose Test Setup

2.1 Test Overview

General test procedures adhere to MIL-STD-883, Method 1017 as a guide for neutron irradiation. The TPS7H6005-SEP was electrically tested using the production automated test equipment (ATE) program at an ambient room temperature of 25°C before and after neutron irradiation.

2.2 Test Facility

The utilized test facility is the Fast Neutron Irradiation (FNI) Facility of University of Massachusetts Lowell Research Reactor. The neutron fluence for this irradiation was measured using ASTM E-265 *Measuring Reaction Rates and Fast Neutron Fluence by Radioactivation of Sulfur-32* and correlated to the measured reactor power level. All irradiation conditions required under ASTM 722 were met, this includes: neutron fluence, distribution, and uncertainty. The Average Integrated Neutron Fluence, 1-MeV(Si) equivalent, reflects these factors. Detailed information of the radiation facility is available at the following link:

UNIVERSITY OF MASSACHUSETTS LOWELL RESEARCH REACTOR

2.3 Test Setup Details

Devices were irradiated at three fluence levels in unbiased conditions: 1.0×10^{12} n/cm^2, 5.0×10^{12} n/cm^2 and 1.0×10^{13} n/cm^2. See the details in Table 2-1.

2.4 Test Configuration and Condition

Table 2-1. Neutron Irradiation Conditions

GROUP	SAMPLE QTY	NEUTRON FLUENCE (n/cm^2)	BIAS
A	4	1.0×10^{12}	Unbias
B	4	5.0×10^{12}	Unbias
C	4	1.0×10^{13}	Unbias
Correlation Units	2	N/A	N/A

3 NDD Characterization Test Results

3.1 NDD Characterization Summary

The results show that all devices were fully functional and within specification limits. A sample size of twelve units was exposed for neutron irradiation and an additional unirradiated control unit was used as correlation. Overall, the TPS7H6005-SEP showed a strong degree of hardness to Neutron irradiation up to fluence level 1 × 10^{13} n/cm^2. The measurements taken post-irradiation for each sample set showed a marginal shift for most parameters at each fluence level.

The parameters that did show a greater degree of change between pre- and post-irradiation were still within the electrical performance characteristics specified in the data sheet electrical parameters. See Section 3.2 for associated tests. Electrical testing is done for pre- and post- neutron irradiation by ATE. ATE electrical test is done at an ambient room temperature of 25°C.

See Appendix A for NDD report up to 1 × 10^{13} n/cm^2.

3.2 Data Sheet Electrical Parameter Characteristics

Specifications are at ambient temperature TA = 25°C, VIN = 10V to 14V, VBP5L = VBP5H = 5V, and no load on LOH, LOL, HOH, and HOL (unless otherwise noted).

Table 3-1. TPS7H6005-SEP Data Sheet Electrical Parameters

Parameter		Test Conditions		MIN	MAX	UNIT	Test Number
SUPPLY CURRENTS							
I_{QLS}	Low-side quiescent current	VIN = 12V, BOOT = 10V	MODE = PWM, EN = 0V		6.8	mA	35.0, 36.0, 37.0
			MODE = IIM LI = HI = 0V		8		35.2, 36.2, 37.2
I_{QHS}	High-side quiescent current	VIN = 12V, BOOT = 10V	MODE = PWM EN = 0V		6.3	mA	35.1, 36.1, 37.1
			MODE = IIM LI = HI = 0V		6.3		35.3, 36.3, 37.3
I_{OP_LS}	Low-side operating current	MODE = PWM, no load for HOL and HOH	f = 500kHz		9	mA	35.6, 36.6, 37.6
			f = 1MHz		11		35.8, 36.8, 37.8
			f = 2MHz		16		35.10, 36.10, 37.10
			f = 5MHz		30		35.12, 36.12, 37.12
		MODE = IIM, no load for HOL and HOH	f = 500kHz		9		35.14, 36.14, 37.14
			f = 1MHz		12		35.16, 36.16, 37.16
			f = 2MHz		17		35.18, 36.18, 37.18
			f = 5MHz		30		35.20, 36.20, 37.20
I_{OP_HS}	High-side operating current	MODE = PWM, no load for HOL and HOH	f = 500kHz		6.5	mA	35.7, 36.7, 37.7
			f = 1MHz		8		35.9, 36.9, 37.9
			f = 2MHz		10.5		35.11, 36.11, 37.11
			f = 5MHz		19		35.13, 36.13, 37.13
		MODE = IIM, no load for HOL and HOH	f = 500kHz		6.5		35.15, 36.15, 37.15
			f = 1MHz		8		35.17, 36.17, 37.17
			f = 2MHz		10.5		35.19, 36.19, 37.19
			f = 5MHz		15		35.21, 36.21, 37.21
GATE DRIVER							
V_{OL}	Low-level output voltage	I_{OL} = 100mA			0.15	V	45.0, 46.0, 47.0
BP5x – V_{OH}	High-level output voltage	I_{OH} = 100mA			0.3	V	45.2, 46.2, 47.2
I_{OH}	Peak source current	HOH, LOH = 0V, BP5x = 5V		0.7	2.3	A	50.0, 50.1, 51.0, 51.1, 52.0, 52.1
I_{OL}	Peak sink current	HOL, LOL = 5V, BP5x = 5V		1.6	4.6	A	50.2, 51.2, 52.2
INTERNAL REGULATORS							
V_{BP5L}	Low-side 5V regulator output voltage	C_{BP5L} = 1μF		4.75	5.175	V	60.1, 60.4, 60.7, 60.10, 60.13, 60.16, 60.19, 60.22, 61.1, 61.4, 61.7, 61.10, 61.13, 61.16, 61.19, 61.22, 62.1, 62.4, 62.7, 62.10, 62.13, 62.16, 62.19, 62.22
V_{BP5H}	High-side 5V regulator output voltage	C_{BP5H} = 1μF		4.75	5.175	V	60.2, 60.5, 60.8, 60.11, 60.14, 60.17, 60.20, 60.23, 61.2, 61.5, 61.8, 61.11, 61.14, 61.17, 61.20, 61.23, 62.2, 62.5, 62.8, 62.11, 62.14, 62.17, 62.20, 62.23
V_{BP7L}	7V regulator output voltage	C_{BP7L} = 1μF		6.65	7.35	V	60.0, 60.3, 60.6, 60.9, 60.12, 60.15, 60.18, 60.21, 61.0, 61.3, 61.6, 61.9, 61.12, 61.15, 61.18, 61.21, 61.23, 62.0, 62.3, 62.6, 62.9, 62.12, 62.15, 62.18, 62.21
UNDERVOLTAGE PROTECTION							
$BP5H_R$	BP5H UVLO rising threshold	C_{BP5H} = 1μF		4	4.5	V	85.1, 86.1, 87.1(1)
$BP5H_F$	BP5H UVLO falling threshold	C_{BP5H} = 1μF		3.8	4.3	V	85.2, 86.2, 87.2(1)
$BP5L_R$	BP5L UVLO rising threshold	C_{BP5L} = 1μF		4.	4.5	V	80.1, 81.1, 82.1(1)
$BP5L_F$	BP5L UVLO falling threshold	C_{BP5L} = 1μF		3.8	4.3	V	80.2, 81.2, 82.2(1)

Table 3-1. TPS7H6005-SEP Data Sheet Electrical Parameters (continued)

Parameter		Test Conditions		MIN	MAX	UNIT	Test Number
BP7L$_R$	BP7L UVLO rising threshold	C_{BP7L} = 1µF		6.2	6.8	V	80.4, 81.4, 82.4(1)
BP7L$_F$	BP7L UVLO falling threshold	C_{BP7L} = 1µF		5.9	6.5	V	80.5, 81.5, 82.5(1)
VIN$_R$	VIN UVLO rising threshold			8	9	V	70.0
VIN$_F$	VIN UVLO falling threshold			7.5	8.5	V	70.1
BOOT$_R$	BOOT UVLO rising threshold			6.6	7.4	V	75.0
BOOT$_F$	BOOT UVLO falling threshold			6.2	7	V	75.1
INPUT PINS							
V_{IR}	Input rising edge threshold			1.80	2.65	V	90.0, 91.0, 92.0, 90.3, 91.3, 92.3
V_{IF}	Input falling edge threshold			1.15	1.85	V	90.1, 91.1, 92.1, 90.4, 91.4, 92.4
R_{PD}	Input pull-down resistance	V = 2.15V applied at input (EN_HI or PWM_LI)		100	400	kΩ	90.6, 90.7, 91.6, 91.7, 92.6, 92.7
PROGRAMMABLE DEAD TIME							
T_{DLH}	LO off to HO on dead time	MODE = PWM, LO falling to HO rising (90% to 10%), f ≤ 2MHz	RLH = 3.32kΩ	0	10	ns	95.0, 95.5, 95.10, 96.0, 96.5, 96.10, 97.0, 97.5, 97.10
			RLH = 11.8kΩ	8	15.5		95.1, 95.6, 95.11, 96.1, 96.6, 96.11, 97.1, 97.6, 97.11
			RLH = 21kΩ	15.5	24		95.2, 95.7, 95.12, 96.2, 96.7, 96.12, 97.2, 97.7, 97.12
			RLH = 52.3kΩ	36	59		95.3, 95.8, 95.13, 96.3, 96.8, 96.13, 97.3, 97.8, 97.13
			RLH = 105kΩ	74	113.5		95.4, 95.9, 95.14, 96.4, 96.9, 96.14, 97.4, 97.9, 97.14
T_{DHL}	HO off to LO on dead time	MODE = PWM, HO falling to LO rising (90% to 10%), f ≤ 2MHz	RHL = 7.87kΩ	0	10	ns	95.19, 95.24, 95.29, 96.19, 96.24, 96.29, 97.19, 97.24, 97.29
			RHL = 13.3kΩ	6	14		95.20, 95.25, 95.30, 96.20, 96.25, 96.30, 97.20, 97.25, 97.30
			RHL = 23.7kΩ	16	24.5		95.21, 95.26, 95.31, 96.21, 96.26, 96.31, 97.21, 97.26, 97.31
			RHL = 57.6kΩ	44	61		95.22, 95.27, 95.32, 96.22, 96.27, 96.32, 97.22, 97.27, 97.32
			RHL = 113kΩ	81	125		95.23, 95.28, 95.33, 96.23, 96.28, 96.33, 97.23, 97.28, 97.33
BOOTSTRAP DIODE SWITCH							
	Bootstrap diode switch parallel resistance	I_{BST_SW} = 1mA		0.8	1.2	kΩ	100.1, 101.1, 102.1
POWER GOOD							
	Logic-low output	I_{FLT}= 1mA			0.4	V	105.0, 106.0, 107.0
	PGOOD internal resistance	BP5L = 5V, BP7L = 7V, VIN = 12V		0.7	1.9	MΩ	105.2, 106.2, 107.2
	Minimum BP5L voltage for valid PGOOD output				2.85	V	105.1, 106.1, 107.1

(1) Tests are only tested in production or SPI test mode.

Table 3-2. TPS7H6005-SEP Switching Characteristics

Parameter		Test Conditions		MIN	MAX	UNIT	Test Number
t_{LPHL}	LO turnoff propagation delay	MODE = PWM	PWM rising to LOL falling		48	ns	110.0, 111.0, 112.0
		MODE = IIM	LI falling to LOL falling		38	ns	110.3, 110.7, 111.3, 111.7, 112.3, 112.7
t_{LPLH}	LO turnon propagation delay	MODE = IIM	LI rising to LOH rising		38	ns	110.2, 110.6, 111.2, 111.6, 112.2, 112.6
t_{HPHL}	HO turnoff propagation delay	MODE = PWM	PWM falling to HOL falling		50	ns	110.1, 111.1, 112.1
		MODE = IIM	HI falling to HOL falling		40		110.5, 110.9, 111.5, 111.9, 112.5, 112.9
t_{HPLH}	HO turnon propagation delay	MODE = IIM	HI rising to HOH rising		40	ns	110.4, 110.8, 111.4, 111.8, 112.4, 112.8
t_{MON}	Delay matching LO on and HO off	MODE = IIM			12	ns	110.12, 111.12, 112.12
t_{MOFF}	Delay matching LO off and HO on	MODE = IIM			4	ns	110.11, 110.13, 111.11, 111.13, 112.11, 112.13
t_{HRC}	HO rise time	C_L = 1000pF	10% to 90%		7.5	ns	115.0, 116.0, 117.0
t_{LRC}	LO rise time				7.5	ns	115.2, 116.2, 117.2
t_{HFC}	HO fall time		90% to 10%		5.5	ns	115.1, 116.1, 117.1
t_{LFC}	LO fall time				5.5	ns	115.3, 116.3, 117.3
t_{PW_IIM}	Minimum input pulse width (turn-on)	MODE = IIM			8	ns	120.0, 120.2, 120.4, 121.0, 121.2, 121.4, 122.0, 122.2, 122.4
$t_{PW\_IIM\_OFF}$	Minimum input pulse width (turn-off)	MODE = IIM			12	ns	120.1, 120.3, 120.5, 121.1, 121.3, 121.5, 122.1, 122.3, 122.5

4 Applicable and Reference Documents

4.1 Applicable Documents

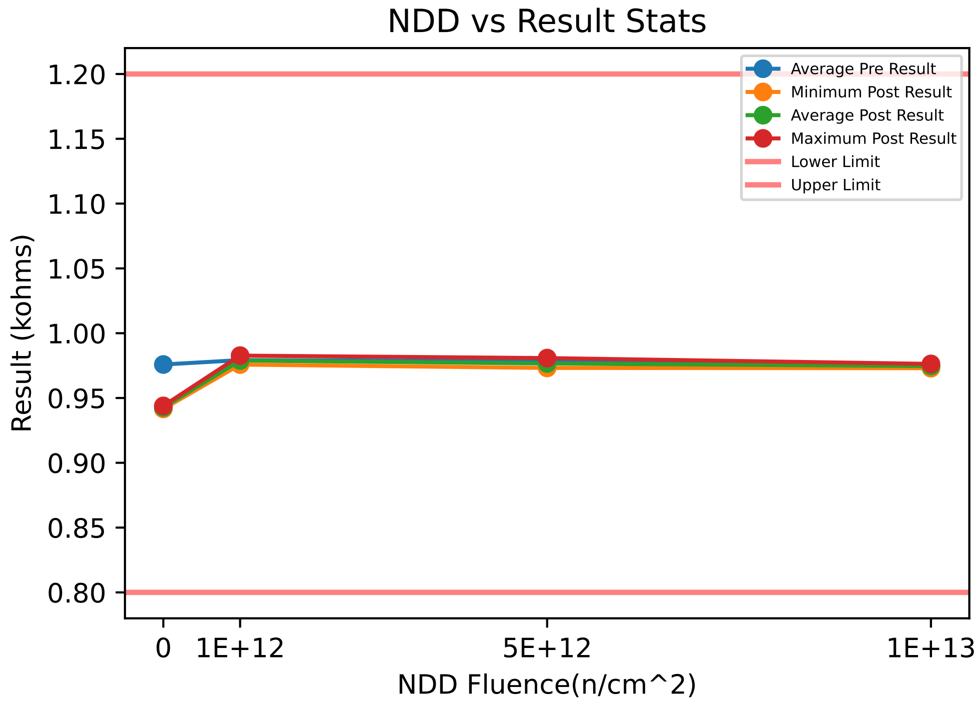
- Texas Instruments, *TPS7H6005-SP Radiation-Hardness-Assured 200-V, 1.3A, 2.5A, Half-Bridge GaN FET Gate Driver*, data sheet.
- Texas Instruments, *TPS7H6005EVM-CVAL Evaluation Module User's Guide*, EVM user's guide.

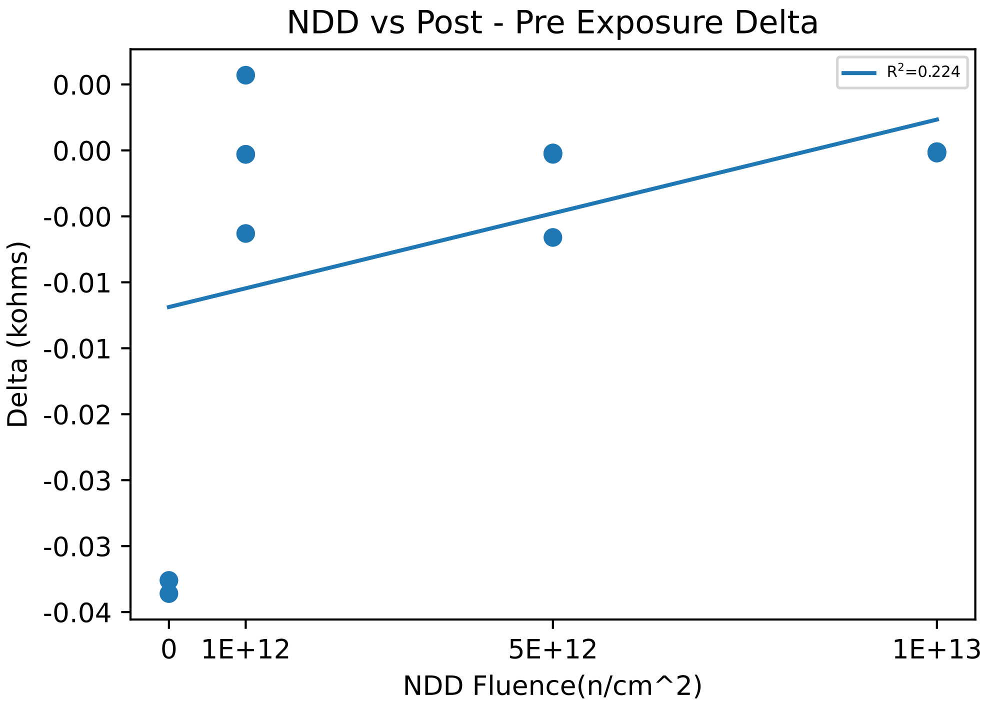
4.2 Reference Documents

Texas Instruments neutron irradiation test follow the guideline from MIL-STD-883 TM 1017. The document is available in Defense Logistic Agency's website.

A Appendix: NDD Report Data

Device Test: 100.1 R_BST_SW_PARALLEL(_Bootstrap Diode Switch Parallel Resistance VIN_10V)





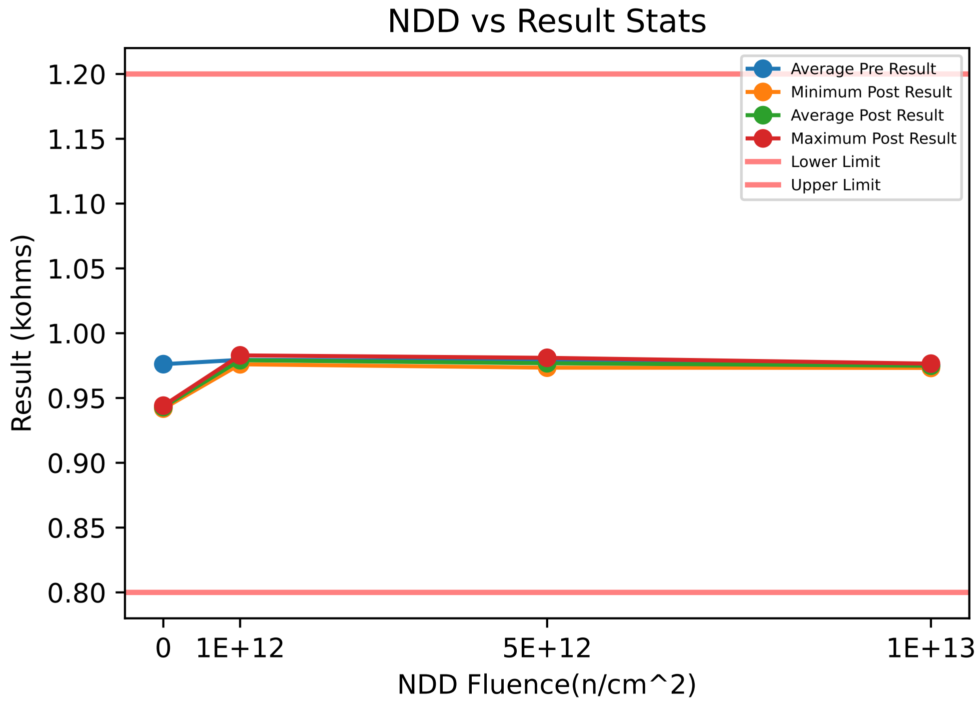
Test Results (Lower Limit = 0.8, Upper Limit = 1.2 (kohms))

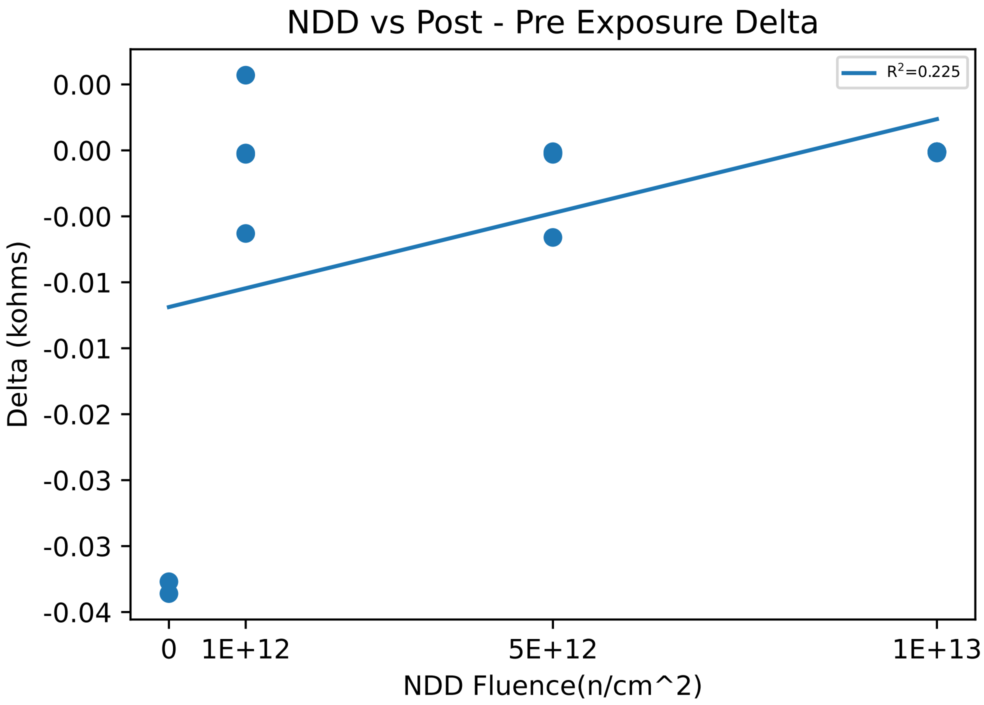
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	0.9775	0.9439	-0.0336
2	0	Correlation	0.9742	0.9416	-0.0326
30	1e+12	NDD unbiased	0.977	0.9827	0.0057
31	1e+12	NDD unbiased	0.983	0.9767	-0.0063
32	1e+12	NDD unbiased	0.9761	0.9758	-0.0003
33	1e+12	NDD unbiased	0.9808	0.9805	-0.0003
44	5e+12	NDD unbiased	0.9795	0.9792	-0.0003
45	5e+12	NDD unbiased	0.9798	0.9732	-0.0066
46	5e+12	NDD unbiased	0.981	0.9808	-0.0002
47	5e+12	NDD unbiased	0.9734	0.9732	-0.0002
50	1e+13	NDD unbiased	0.9731	0.973	-0.0001
51	1e+13	NDD unbiased	0.9754	0.9753	-0.0001
52	1e+13	NDD unbiased	0.9765	0.9763	-0.0002
53	1e+13	NDD unbiased	0.9742	0.974	-0.0002

Test Statistics (kohms)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.9742	0.97585	0.9775	0.0023335	0.9416	0.94275	0.9439	0.0016263	-0.0336	-0.0331	-0.0326	0.00070711
1e+12	0.9761	0.97923	0.983	0.0032377	0.9758	0.97893	0.9827	0.0032377	-0.0063	-0.0003	0.0057	0.004899
5e+12	0.9734	0.97842	0.981	0.0034121	0.9732	0.9766	0.9808	0.0039799	-0.0066	-0.001825	-0.0002	0.0031837
1e+13	0.9731	0.9748	0.9765	0.001472	0.973	0.97465	0.9763	0.001448	-0.0002	-0.00015	-0.0001	5.7735e-05

Device Test: 101.1 R_BST_SW_PARALLEL(_Bootstrap Diode Switch Parallel Resistance VIN_12V)





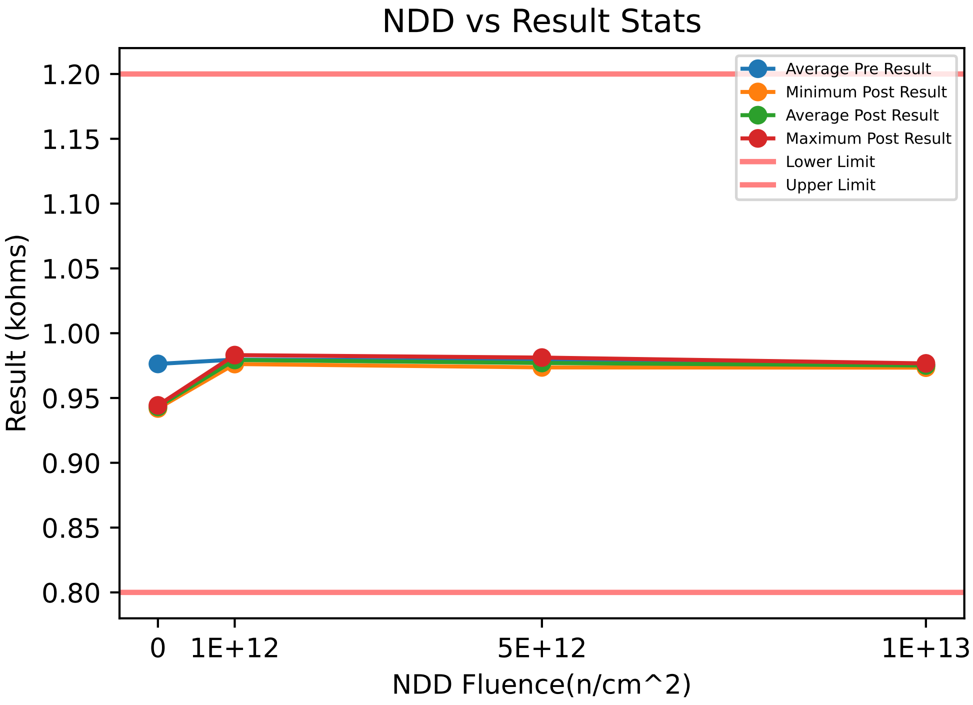
Test Results (Lower Limit = 0.8, Upper Limit = 1.2 (kohms))

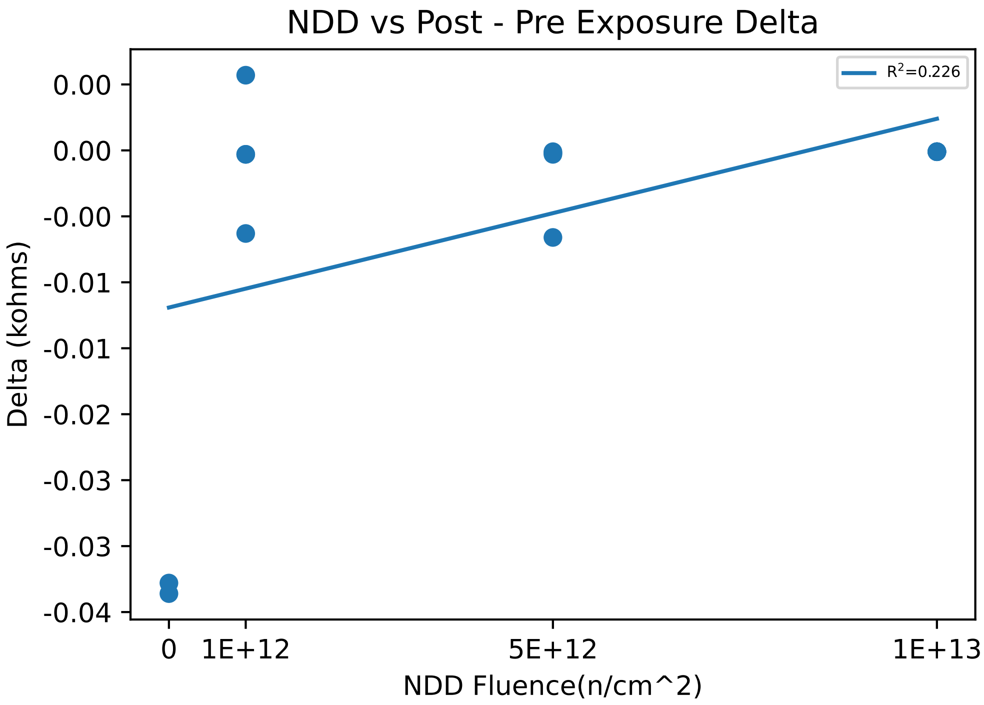
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	0.9777	0.9441	-0.0336
2	0	Correlation	0.9745	0.9418	-0.0327
30	1e+12	NDD unbiased	0.9772	0.9829	0.0057
31	1e+12	NDD unbiased	0.9832	0.9769	-0.0063
32	1e+12	NDD unbiased	0.9763	0.976	-0.0003
33	1e+12	NDD unbiased	0.981	0.9808	-0.0002
44	5e+12	NDD unbiased	0.9797	0.9794	-0.0003
45	5e+12	NDD unbiased	0.98	0.9734	-0.0066
46	5e+12	NDD unbiased	0.9811	0.981	-0.0001
47	5e+12	NDD unbiased	0.9736	0.9734	-0.0002
50	1e+13	NDD unbiased	0.9733	0.9732	-0.0001
51	1e+13	NDD unbiased	0.9756	0.9755	-0.0001
52	1e+13	NDD unbiased	0.9767	0.9765	-0.0002
53	1e+13	NDD unbiased	0.9744	0.9743	-0.0001

Test Statistics (kohms)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.9745	0.9761	0.9777	0.0022627	0.9418	0.94295	0.9441	0.0016263	-0.0336	-0.03315	-0.0327	0.0006364
1e+12	0.9763	0.97942	0.9832	0.0032377	0.976	0.97915	0.9829	0.0032542	-0.0063	-0.000275	0.0057	0.0048992
5e+12	0.9736	0.9786	0.9811	0.0033872	0.9734	0.9768	0.981	0.0039799	-0.0066	-0.0018	-0.0001	0.003201
1e+13	0.9733	0.975	0.9767	0.001472	0.9732	0.97488	0.9765	0.0014338	-0.0002	-0.000125	-0.0001	5e-05

Device Test: 102.1 R_BST_SW_PARALLEL(_Bootstrap Diode Switch Parallel Resistance VIN_14V)


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

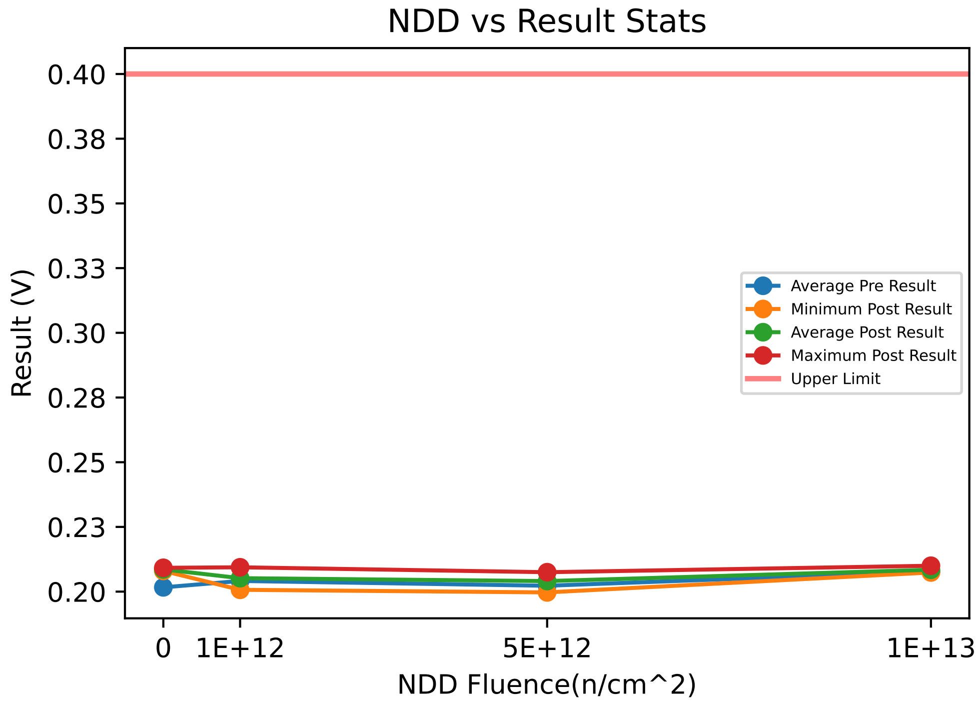
Test Results (Lower Limit = 0.8, Upper Limit = 1.2 (kohms))

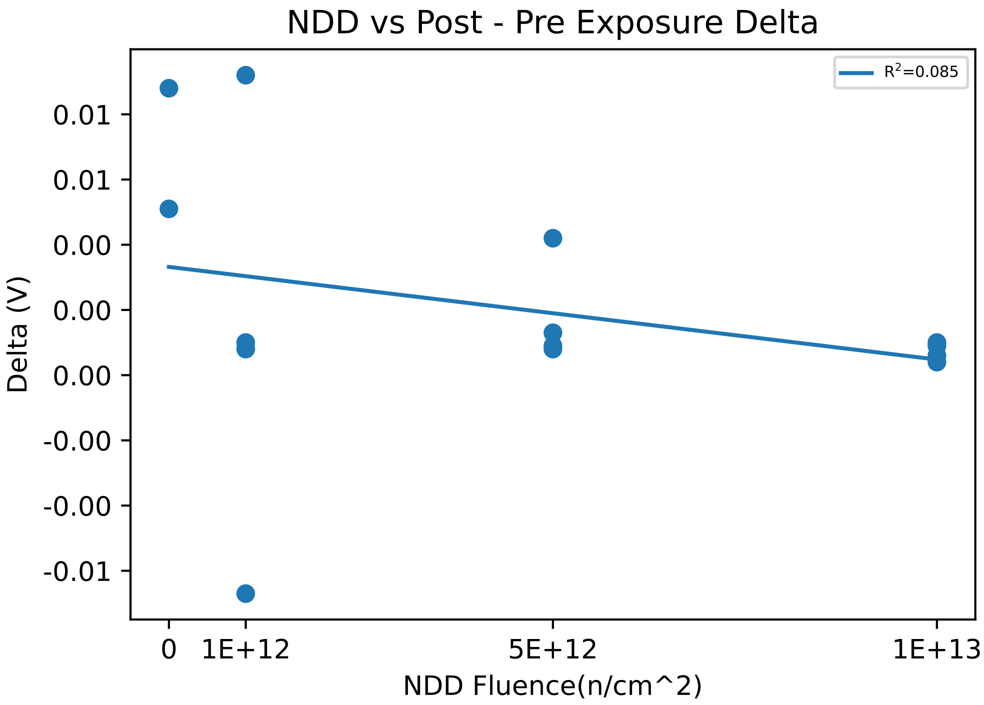
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	0.9779	0.9443	-0.0336
2	0	Correlation	0.9747	0.9419	-0.0328
30	1e+12	NDD unbiased	0.9774	0.9831	0.0057
31	1e+12	NDD unbiased	0.9834	0.9771	-0.0063
32	1e+12	NDD unbiased	0.9765	0.9762	-0.0003
33	1e+12	NDD unbiased	0.9812	0.9809	-0.0003
44	5e+12	NDD unbiased	0.9799	0.9796	-0.0003
45	5e+12	NDD unbiased	0.9802	0.9736	-0.0066
46	5e+12	NDD unbiased	0.9813	0.9812	-0.0001
47	5e+12	NDD unbiased	0.9738	0.9736	-0.0002
50	1e+13	NDD unbiased	0.9735	0.9734	-0.0001
51	1e+13	NDD unbiased	0.9758	0.9757	-0.0001
52	1e+13	NDD unbiased	0.9768	0.9767	-0.0001
53	1e+13	NDD unbiased	0.9745	0.9744	-0.0001

Test Statistics (kohms)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.9747	0.9763	0.9779	0.0022627	0.9419	0.9431	0.9443	0.0016971	-0.0336	-0.0332	-0.0328	0.00056569
1e+12	0.9765	0.97962	0.9834	0.0032377	0.9762	0.97933	0.9831	0.0032377	-0.0063	-0.0003	0.0057	0.004899
5e+12	0.9738	0.9788	0.9813	0.0033872	0.9736	0.977	0.9812	0.0039799	-0.0066	-0.0018	-0.0001	0.003201
1e+13	0.9735	0.97515	0.9768	0.001448	0.9734	0.97505	0.9767	0.001448	-0.0001	-0.0001	-0.0001	0

Device Test: 105.0 V_PGOOD_OL(_PGOOD Logic Low Outupt)





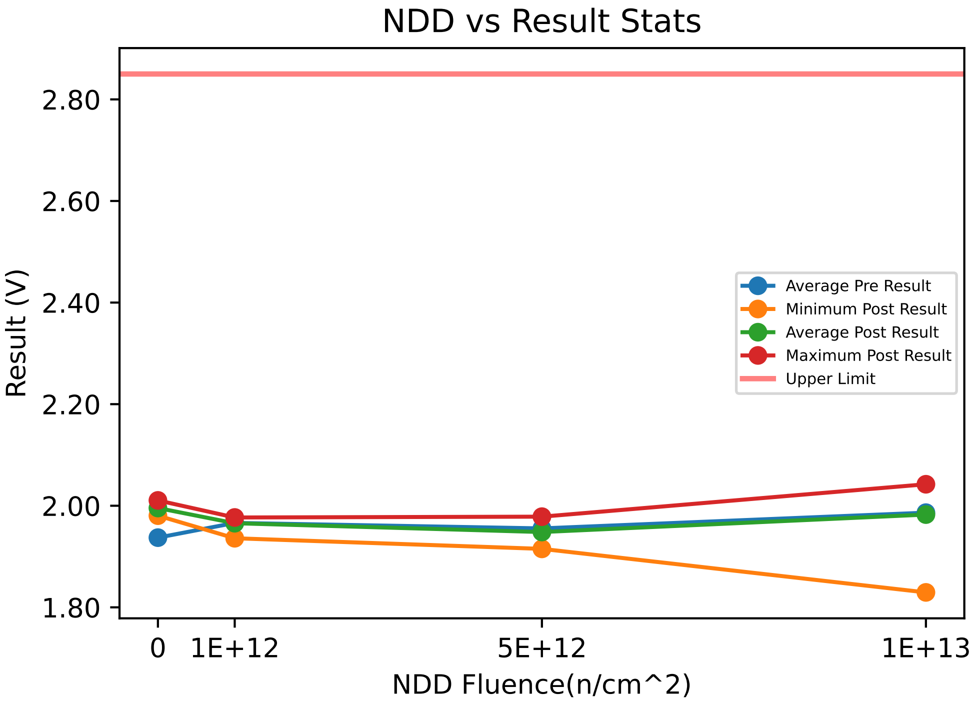
Test Results (Upper Limit = 0.4 (V))

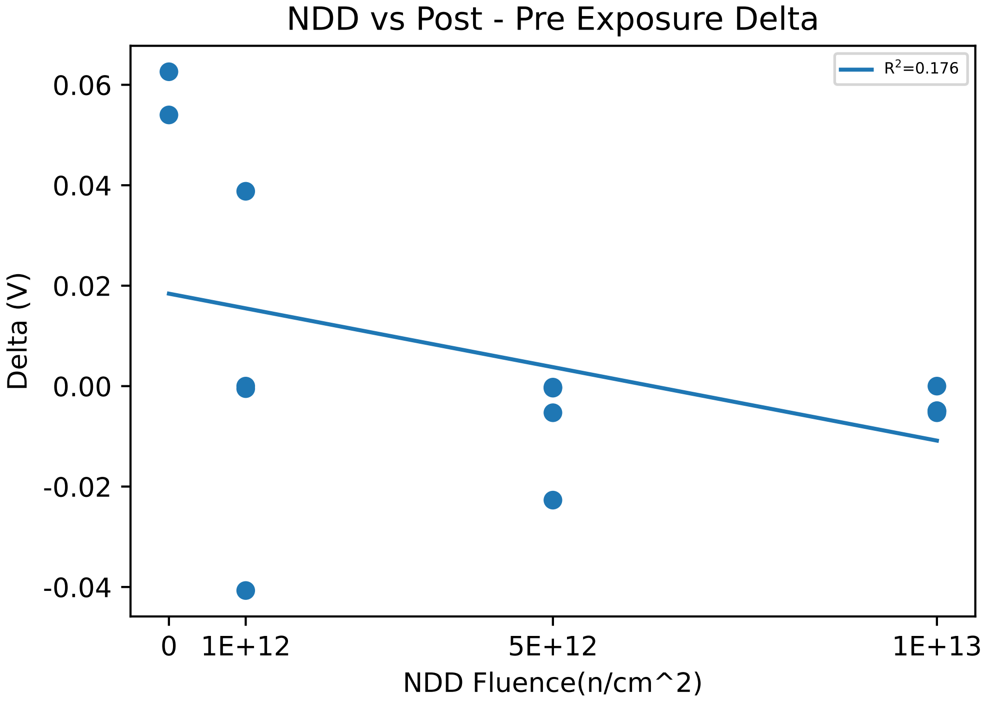
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	0.2004	0.2092	0.0088
2	0	Correlation	0.2029	0.208	0.0051
30	1e+12	NDD unbiased	0.2002	0.2094	0.0092
31	1e+12	NDD unbiased	0.208	0.2013	-0.0067
32	1e+12	NDD unbiased	0.2084	0.2094	0.001
33	1e+12	NDD unbiased	0.1999	0.2007	0.0008
44	5e+12	NDD unbiased	0.2004	0.2017	0.0013
45	5e+12	NDD unbiased	0.2032	0.2074	0.0042
46	5e+12	NDD unbiased	0.1988	0.1997	0.0009
47	5e+12	NDD unbiased	0.2067	0.2075	0.0008
50	1e+13	NDD unbiased	0.2096	0.21	0.0004
51	1e+13	NDD unbiased	0.2077	0.2087	0.001
52	1e+13	NDD unbiased	0.2068	0.2074	0.0006
53	1e+13	NDD unbiased	0.2068	0.2077	0.0009

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.2004	0.20165	0.2029	0.0017678	0.208	0.2086	0.2092	0.00084853	0.0051	0.00695	0.0088	0.0026163
1e+12	0.1999	0.20413	0.2084	0.0047098	0.2007	0.2052	0.2094	0.0048559	-0.0067	0.001075	0.0092	0.0064948
5e+12	0.1988	0.20227	0.2067	0.0034654	0.1997	0.20408	0.2075	0.0039819	0.0008	0.0018	0.0042	0.0016145
1e+13	0.2068	0.20772	0.2096	0.00132	0.2074	0.20845	0.21	0.0011733	0.0004	0.000725	0.001	0.00027538

Device Test: 105.1 V_BP5L_MIN_FOR_PGOOD(_Min BP5L for Valid PGOOD)





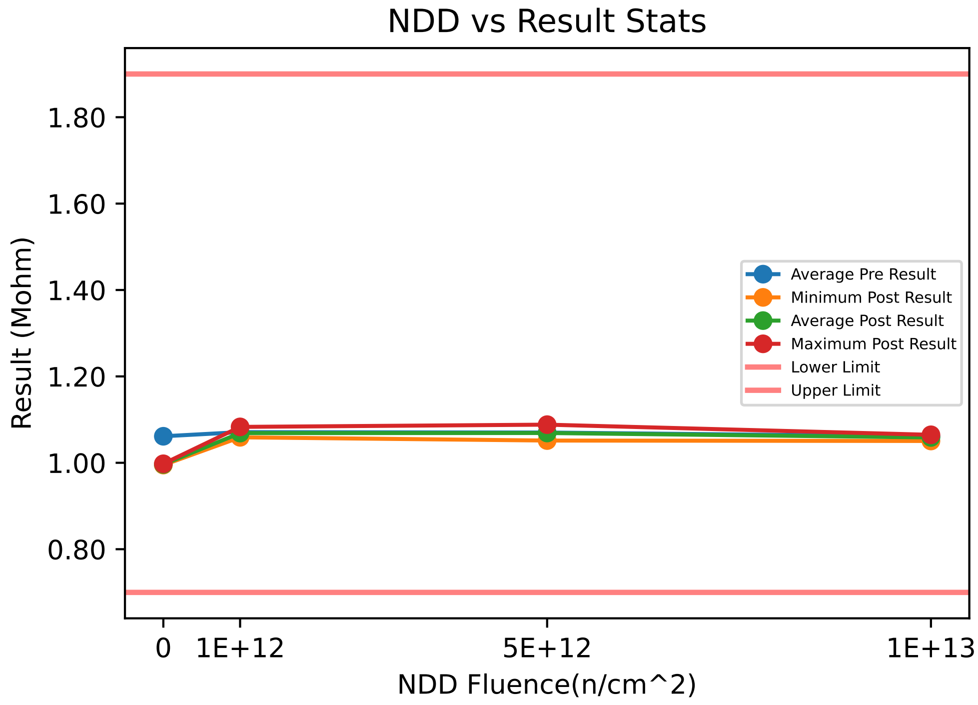
Test Results (Upper Limit = 2.85 (V))

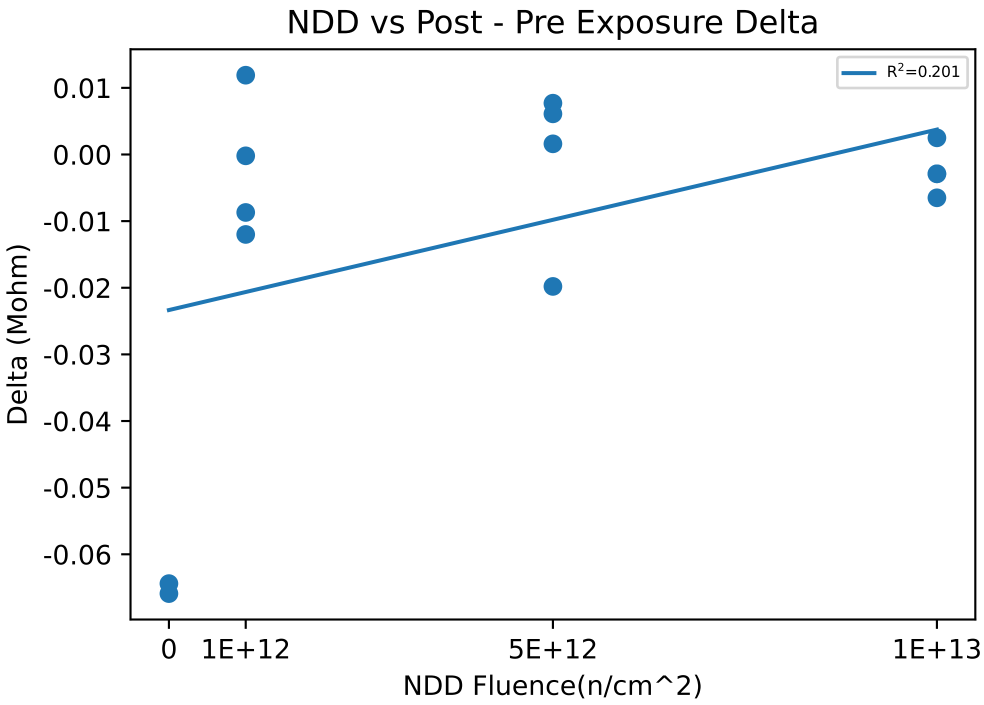
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	1.9265	1.9805	0.054
2	0	Correlation	1.9479	2.0105	0.0626
30	1e+12	NDD unbiased	1.9767	1.936	-0.0407
31	1e+12	NDD unbiased	1.9373	1.9761	0.0388
32	1e+12	NDD unbiased	1.9774	1.9769	-0.0005
33	1e+12	NDD unbiased	1.9733	1.9733	0
44	5e+12	NDD unbiased	1.9262	1.9209	-0.0053
45	5e+12	NDD unbiased	2.0012	1.9785	-0.0227
46	5e+12	NDD unbiased	1.9155	1.9151	-0.0004
47	5e+12	NDD unbiased	1.9787	1.9785	-0.0002
50	1e+13	NDD unbiased	2.0383	2.0334	-0.0049
51	1e+13	NDD unbiased	1.8347	1.8294	-0.0053
52	1e+13	NDD unbiased	2.0253	2.0253	0
53	1e+13	NDD unbiased	2.0472	2.0423	-0.0049

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.9265	1.9372	1.9479	0.015132	1.9805	1.9955	2.0105	0.021213	0.054	0.0583	0.0626	0.0060811
1e+12	1.9373	1.9662	1.9774	0.019333	1.936	1.9656	1.9769	0.019777	-0.0407	-0.0006	0.0388	0.032459
5e+12	1.9155	1.9554	2.0012	0.041171	1.9151	1.9483	1.9785	0.03501	-0.0227	-0.00715	-0.0002	0.010632
1e+13	1.8347	1.9864	2.0472	0.10152	1.8294	1.9826	2.0423	0.10237	-0.0053	-0.003775	0	0.0025237

Device Test: 105.2 I_PGOOD_PD_RES(_PGOOD Internal Resistance VIN_10V)


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

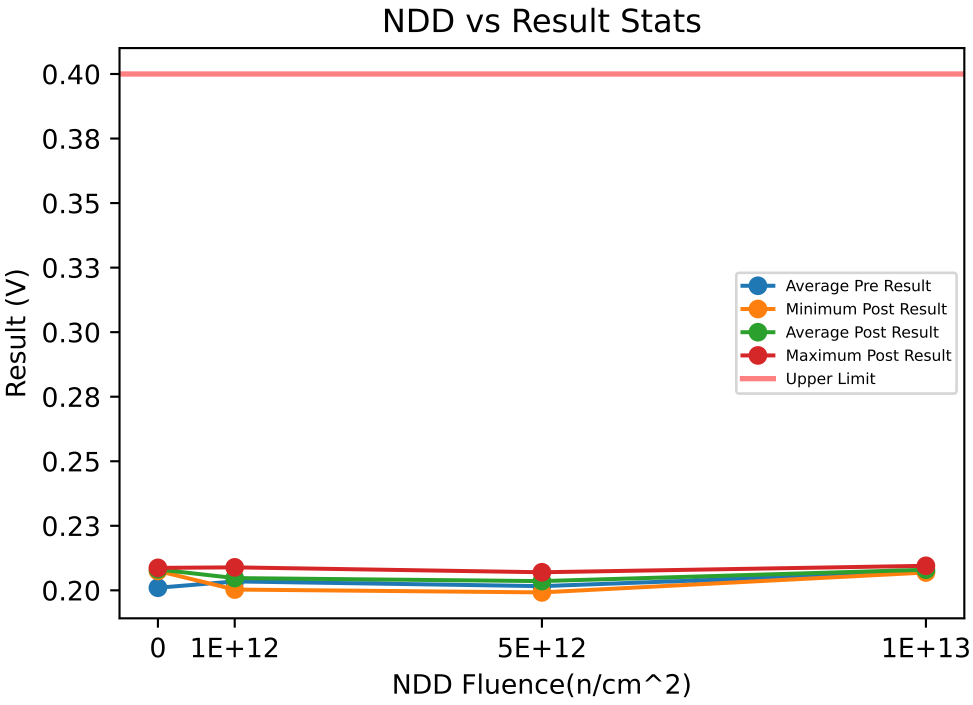
Test Results (Lower Limit = 0.7, Upper Limit = 1.9 (Mohm))

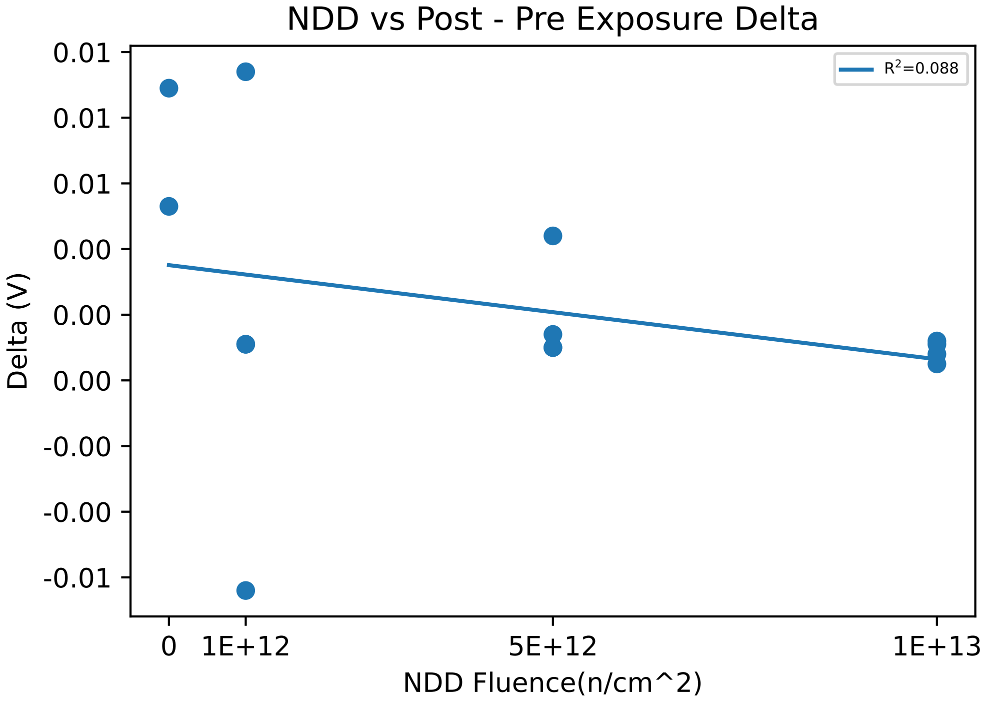
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	1.0636	0.9977	-0.0659
2	0	Correlation	1.0592	0.9948	-0.0644
30	1e+12	NDD unbiased	1.071	1.059	-0.012
31	1e+12	NDD unbiased	1.058	1.0699	0.0119
32	1e+12	NDD unbiased	1.0631	1.0629	-0.0002
33	1e+12	NDD unbiased	1.0918	1.0831	-0.0087
44	5e+12	NDD unbiased	1.0759	1.0775	0.0016
45	5e+12	NDD unbiased	1.0713	1.0515	-0.0198
46	5e+12	NDD unbiased	1.0806	1.0883	0.0077
47	5e+12	NDD unbiased	1.0524	1.0585	0.0061
50	1e+13	NDD unbiased	1.0677	1.0648	-0.0029
51	1e+13	NDD unbiased	1.048	1.0505	0.0025
52	1e+13	NDD unbiased	1.064	1.0611	-0.0029
53	1e+13	NDD unbiased	1.0648	1.0583	-0.0065

Test Statistics (Mohm)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.0592	1.0614	1.0636	0.0031113	0.9948	0.99625	0.9977	0.0020506	-0.0659	-0.06515	-0.0644	0.0010607
1e+12	1.058	1.071	1.0918	0.014878	1.059	1.0687	1.0831	0.010591	-0.012	-0.00225	0.0119	0.010663
5e+12	1.0524	1.07	1.0806	0.012364	1.0515	1.069	1.0883	0.016943	-0.0198	-0.0011	0.0077	0.012731
1e+13	1.048	1.0611	1.0677	0.0088932	1.0505	1.0587	1.0648	0.0060654	-0.0065	-0.00245	0.0025	0.0037108

Device Test: 106.0 V_PGOOD_OL(_PGOOD Logic Low Outupt)





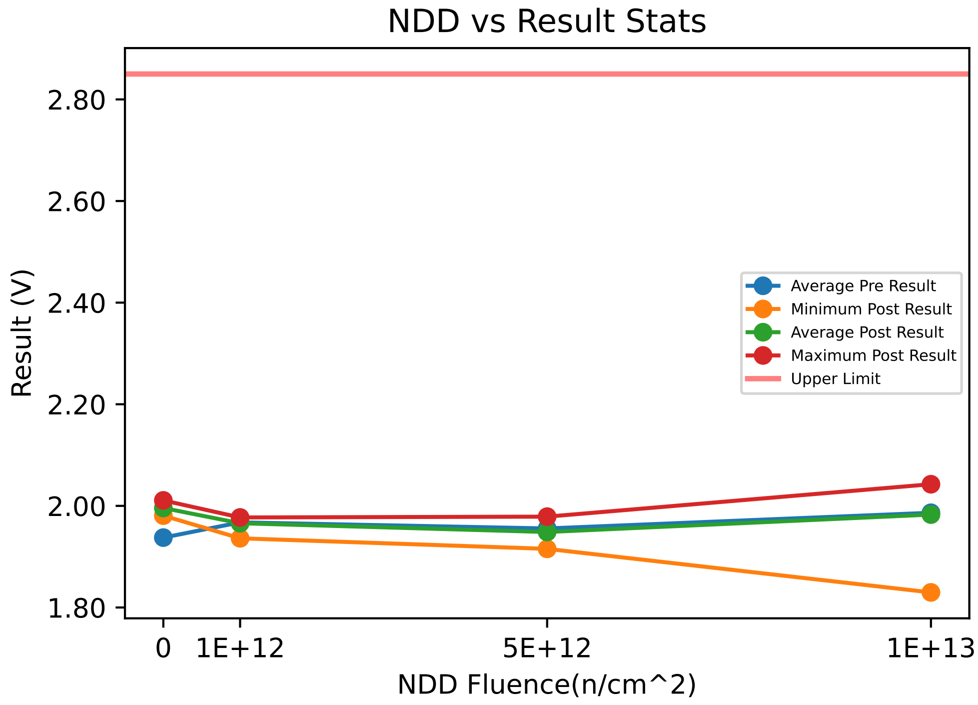
Test Results (Upper Limit = 0.4 (V))

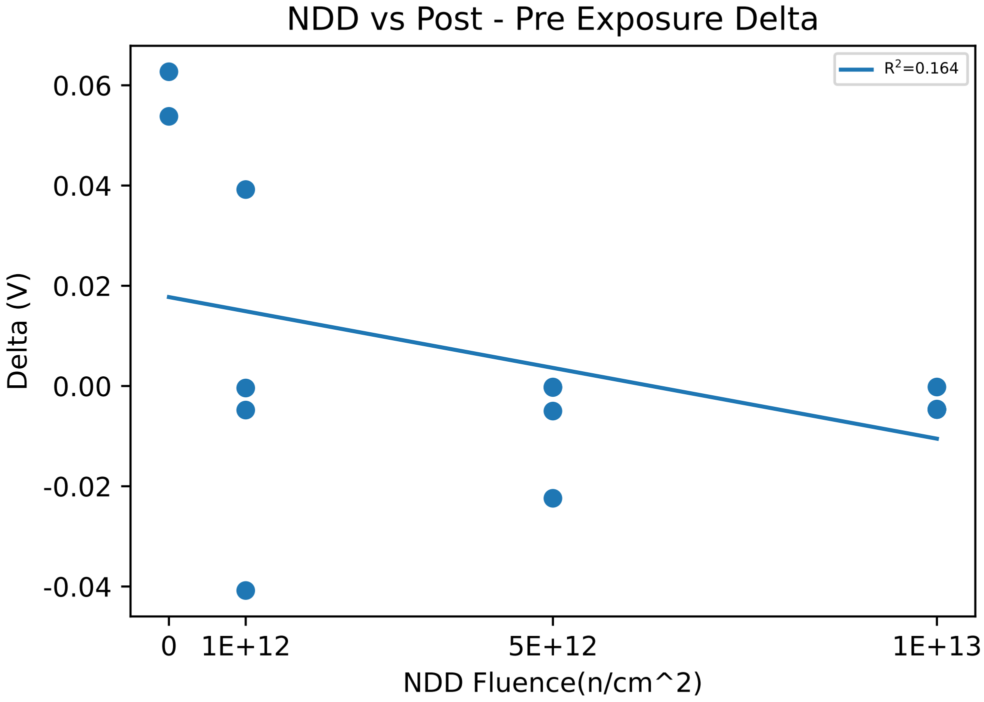
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	0.1998	0.2087	0.0089
2	0	Correlation	0.2022	0.2075	0.0053
30	1e+12	NDD unbiased	0.1995	0.2089	0.0094
31	1e+12	NDD unbiased	0.2073	0.2009	-0.0064
32	1e+12	NDD unbiased	0.2078	0.2089	0.0011
33	1e+12	NDD unbiased	0.1992	0.2003	0.0011
44	5e+12	NDD unbiased	0.1998	0.2012	0.0014
45	5e+12	NDD unbiased	0.2025	0.2069	0.0044
46	5e+12	NDD unbiased	0.1982	0.1992	0.001
47	5e+12	NDD unbiased	0.206	0.207	0.001
50	1e+13	NDD unbiased	0.209	0.2095	0.0005
51	1e+13	NDD unbiased	0.2071	0.2082	0.0011
52	1e+13	NDD unbiased	0.2061	0.2069	0.0008
53	1e+13	NDD unbiased	0.2061	0.2073	0.0012

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.1998	0.201	0.2022	0.0016971	0.2075	0.2081	0.2087	0.00084853	0.0053	0.0071	0.0089	0.0025456
1e+12	0.1992	0.20345	0.2078	0.0047403	0.2003	0.20475	0.2089	0.0047983	-0.0064	0.0013	0.0094	0.0064545
5e+12	0.1982	0.20162	0.206	0.0034141	0.1992	0.20358	0.207	0.0039819	0.001	0.00195	0.0044	0.0016442
1e+13	0.2061	0.20708	0.209	0.0013672	0.2069	0.20797	0.2095	0.0011529	0.0005	0.0009	0.0012	0.00031623

Device Test: 106.1 V_BP5L_MIN_FOR_PGOOD(_Min BP5L for Valid PGOOD)





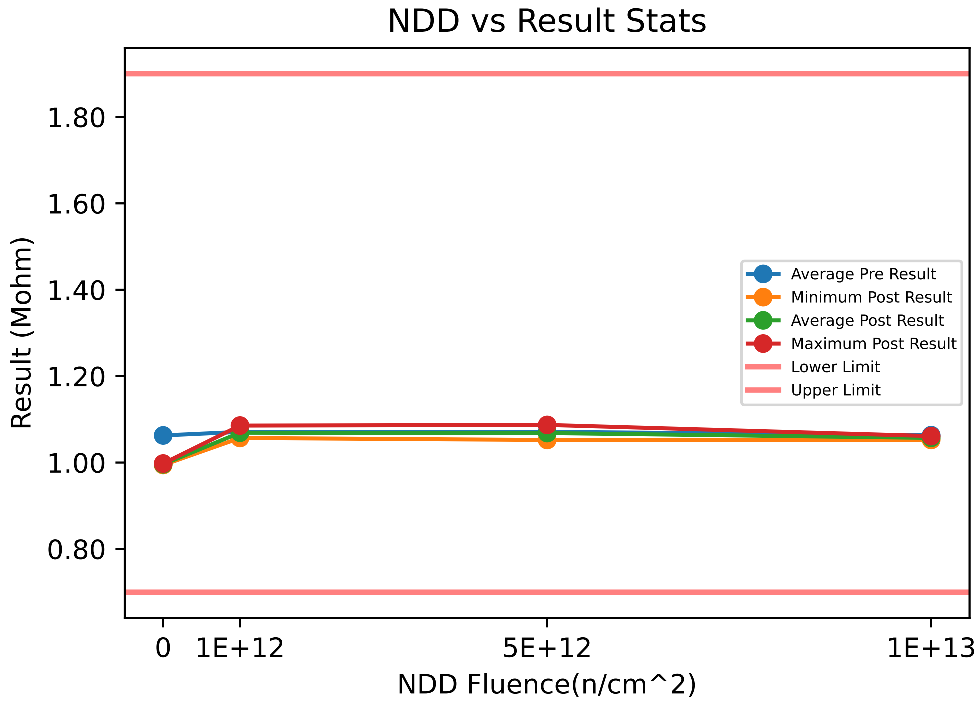
Test Results (Upper Limit = 2.85 (V))

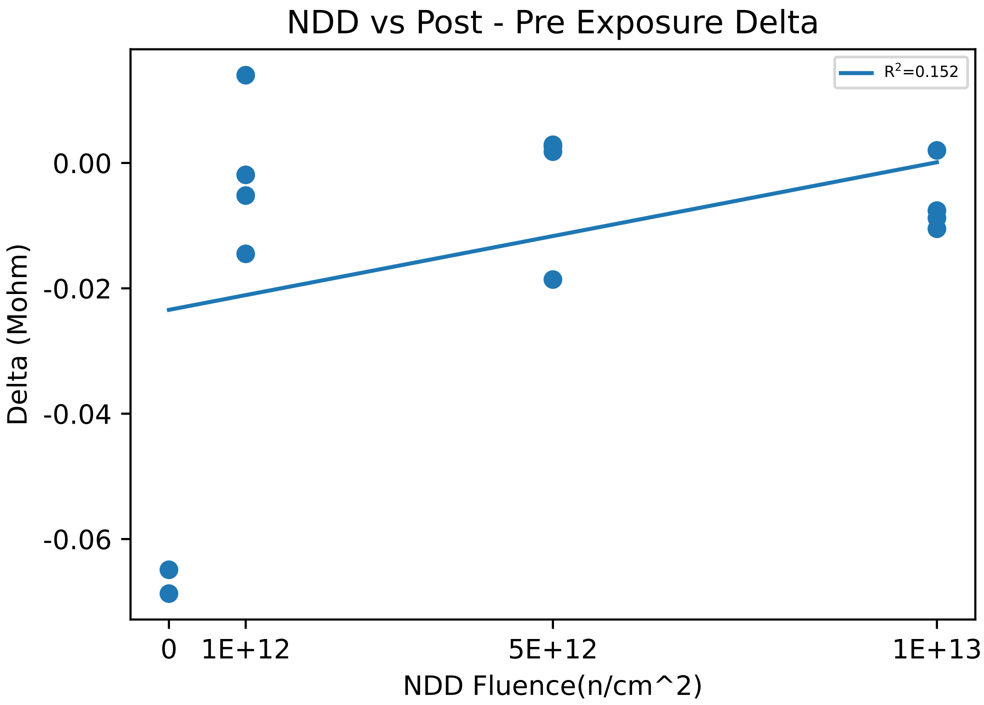
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	1.927	1.9808	0.0538
2	0	Correlation	1.9481	2.0108	0.0627
30	1e+12	NDD unbiased	1.977	1.9362	-0.0408
31	1e+12	NDD unbiased	1.9372	1.9764	0.0392
32	1e+12	NDD unbiased	1.9776	1.9772	-0.0004
33	1e+12	NDD unbiased	1.9783	1.9735	-0.0048
44	5e+12	NDD unbiased	1.9265	1.9215	-0.005
45	5e+12	NDD unbiased	2.0012	1.9788	-0.0224
46	5e+12	NDD unbiased	1.9156	1.9154	-0.0002
47	5e+12	NDD unbiased	1.9789	1.9786	-0.0003
50	1e+13	NDD unbiased	2.0383	2.0336	-0.0047
51	1e+13	NDD unbiased	1.8343	1.8297	-0.0046
52	1e+13	NDD unbiased	2.0258	2.0256	-0.0002
53	1e+13	NDD unbiased	2.0473	2.0426	-0.0047

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.927	1.9375	1.9481	0.01492	1.9808	1.9958	2.0108	0.021213	0.0538	0.05825	0.0627	0.0062933
1e+12	1.9372	1.9675	1.9783	0.020224	1.9362	1.9658	1.9772	0.019814	-0.0408	-0.0017	0.0392	0.032726
5e+12	1.9156	1.9555	2.0012	0.041106	1.9154	1.9486	1.9788	0.034874	-0.0224	-0.006975	-0.0002	0.010524
1e+13	1.8343	1.9864	2.0473	0.1018	1.8297	1.9829	2.0426	0.10235	-0.0047	-0.00355	-0.0002	0.0022338

Device Test: 106.2 I_PGOOD_PD_RES(_PGOOD Internal Resistance VIN_12V)





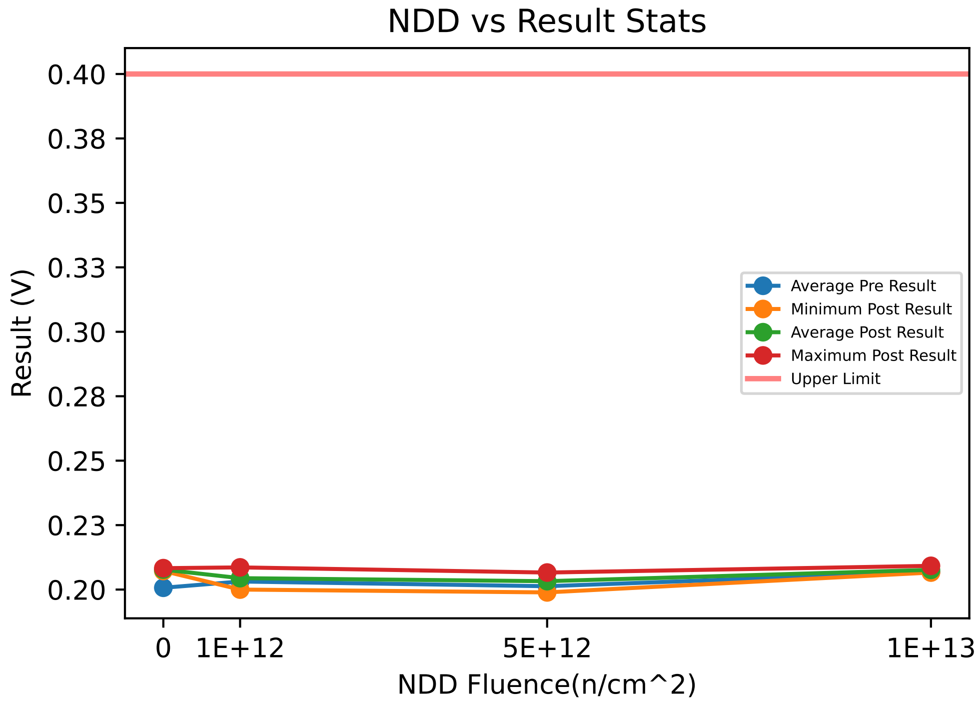
Test Results (Lower Limit = 0.7, Upper Limit = 1.9 (Mohm))

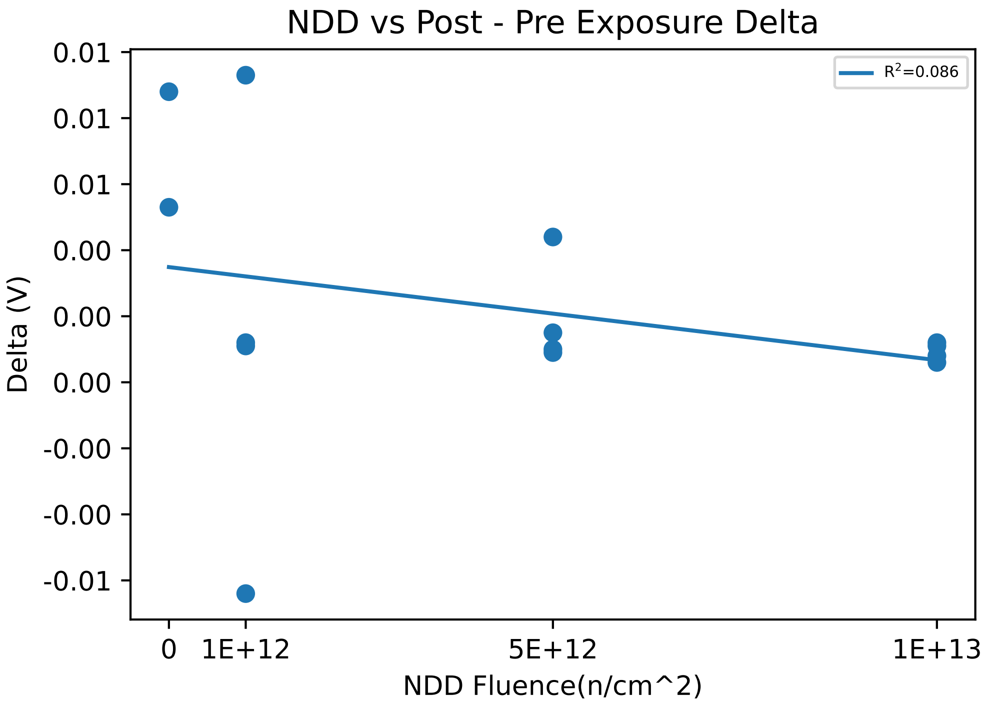
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	1.0664	0.9977	-0.0687
2	0	Correlation	1.0592	0.9943	-0.0649
30	1e+12	NDD unbiased	1.0714	1.0569	-0.0145
31	1e+12	NDD unbiased	1.0588	1.0728	0.014
32	1e+12	NDD unbiased	1.063	1.0611	-0.0019
33	1e+12	NDD unbiased	1.0908	1.0856	-0.0052
44	5e+12	NDD unbiased	1.0761	1.0779	0.0018
45	5e+12	NDD unbiased	1.0709	1.0523	-0.0186
46	5e+12	NDD unbiased	1.0845	1.0871	0.0026
47	5e+12	NDD unbiased	1.053	1.0559	0.0029
50	1e+13	NDD unbiased	1.0701	1.0613	-0.0088
51	1e+13	NDD unbiased	1.0503	1.0523	0.002
52	1e+13	NDD unbiased	1.0676	1.06	-0.0076
53	1e+13	NDD unbiased	1.0654	1.0549	-0.0105

Test Statistics (Mohm)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.0592	1.0628	1.0664	0.0050912	0.9943	0.996	0.9977	0.0024042	-0.0687	-0.0668	-0.0649	0.002687
1e+12	1.0588	1.071	1.0908	0.014201	1.0569	1.0691	1.0856	0.012894	-0.0145	-0.0019	0.014	0.011867
5e+12	1.053	1.0711	1.0845	0.013319	1.0523	1.0683	1.0871	0.016885	-0.0186	-0.002825	0.0029	0.010527
1e+13	1.0503	1.0634	1.0701	0.0089094	1.0523	1.0571	1.0613	0.0042398	-0.0105	-0.006225	0.002	0.0056109

Device Test: 107.0 V_PGOOD_OL(_PGOOD Logic Low Outupt)


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

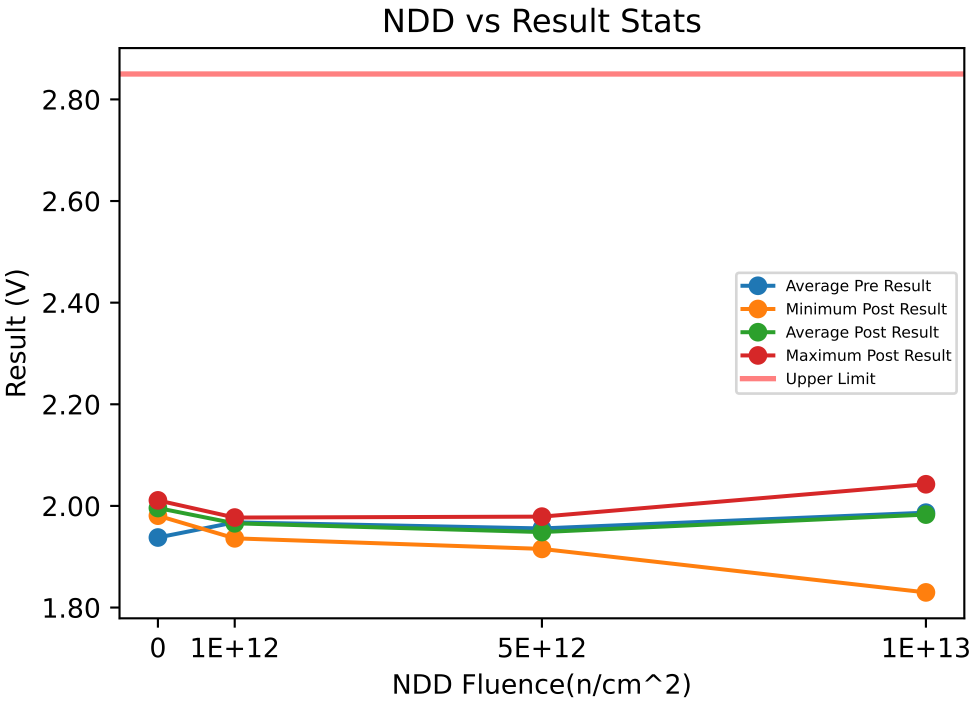
Test Results (Upper Limit = 0.4 (V))

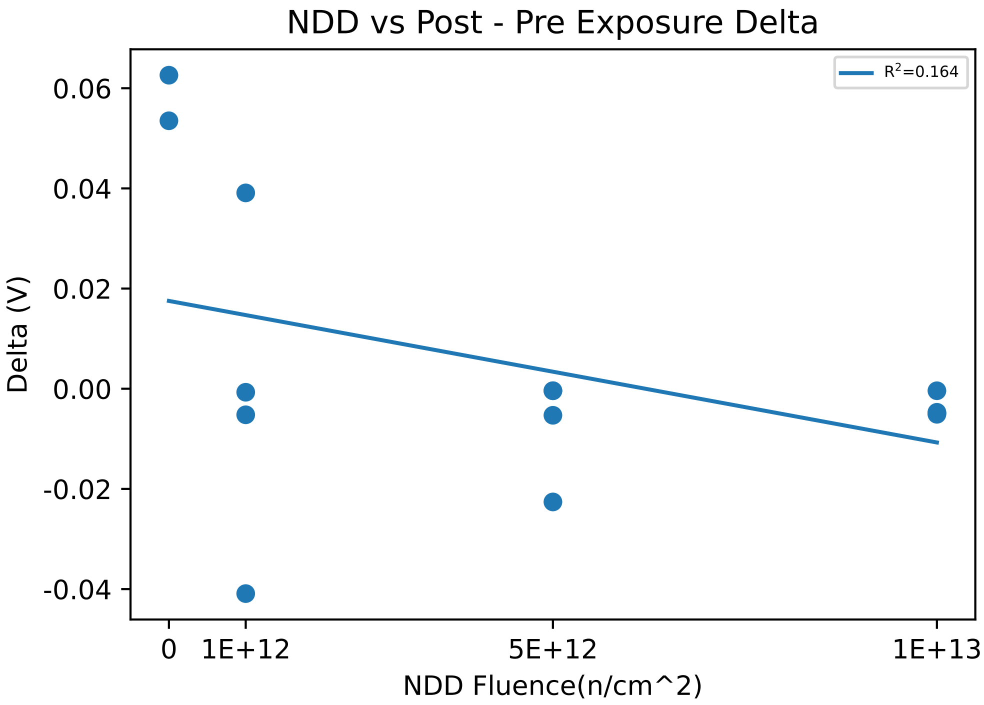
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	0.1995	0.2083	0.0088
2	0	Correlation	0.2019	0.2072	0.0053
30	1e+12	NDD unbiased	0.1992	0.2085	0.0093
31	1e+12	NDD unbiased	0.207	0.2006	-0.0064
32	1e+12	NDD unbiased	0.2074	0.2086	0.0012
33	1e+12	NDD unbiased	0.1989	0.2	0.0011
44	5e+12	NDD unbiased	0.1994	0.2009	0.0015
45	5e+12	NDD unbiased	0.2022	0.2066	0.0044
46	5e+12	NDD unbiased	0.1979	0.1989	0.001
47	5e+12	NDD unbiased	0.2057	0.2066	0.0009
50	1e+13	NDD unbiased	0.2086	0.2092	0.0006
51	1e+13	NDD unbiased	0.2067	0.2079	0.0012
52	1e+13	NDD unbiased	0.2058	0.2066	0.0008
53	1e+13	NDD unbiased	0.2058	0.2069	0.0011

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.1995	0.2007	0.2019	0.0016971	0.2072	0.20775	0.2083	0.00077782	0.0053	0.00705	0.0088	0.0024749
1e+12	0.1989	0.20312	0.2074	0.0047098	0.2	0.20442	0.2086	0.0047696	-0.0064	0.0013	0.0093	0.006412
5e+12	0.1979	0.2013	0.2057	0.0034322	0.1989	0.20325	0.2066	0.0039535	0.0009	0.00195	0.0044	0.0016543
1e+13	0.2058	0.20672	0.2086	0.00132	0.2066	0.20765	0.2092	0.0011733	0.0006	0.000925	0.0012	0.00027538

Device Test: 107.1 V_BP5L_MIN_FOR_PGOOD(_Min BP5L for Valid PGOOD)





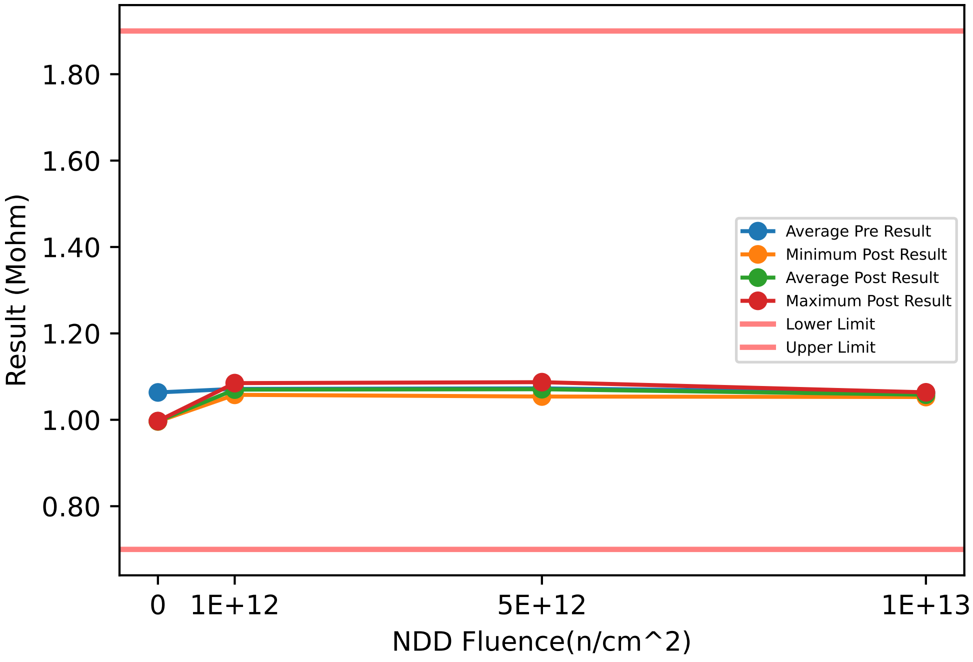
Test Results (Upper Limit = 2.85 (V))

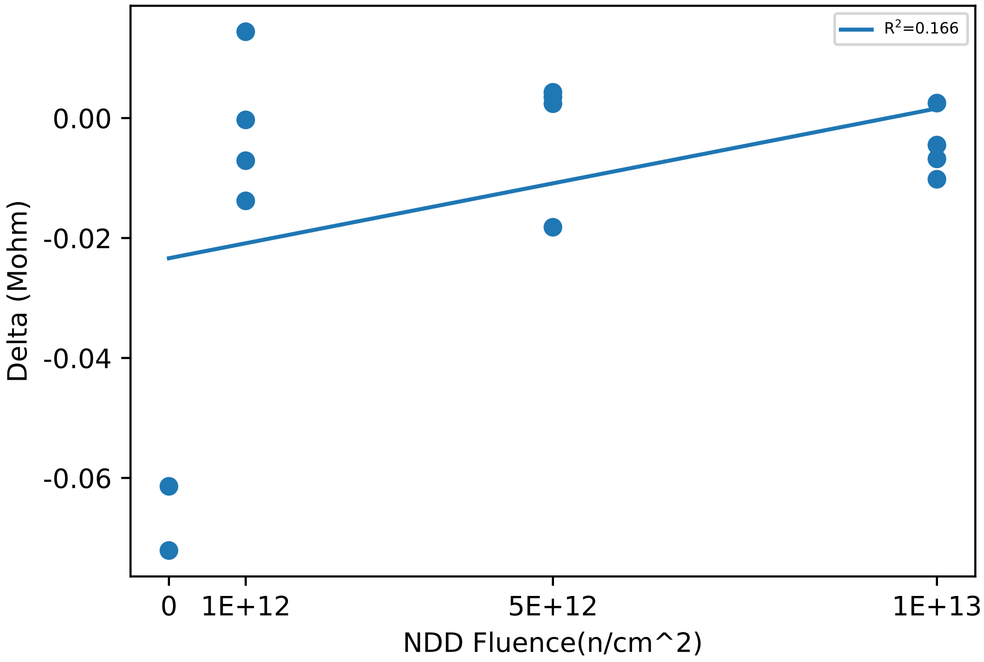
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	1.9273	1.9808	0.0535
2	0	Correlation	1.9483	2.0109	0.0626
30	1e+12	NDD unbiased	1.9771	1.9362	-0.0409
31	1e+12	NDD unbiased	1.9373	1.9764	0.0391
32	1e+12	NDD unbiased	1.9778	1.9771	-0.0007
33	1e+12	NDD unbiased	1.9785	1.9733	-0.0052
44	5e+12	NDD unbiased	1.9265	1.9212	-0.0053
45	5e+12	NDD unbiased	2.0015	1.9789	-0.0226
46	5e+12	NDD unbiased	1.9158	1.9154	-0.0004
47	5e+12	NDD unbiased	1.979	1.9786	-0.0004
50	1e+13	NDD unbiased	2.0388	2.0337	-0.0051
51	1e+13	NDD unbiased	1.8347	1.8298	-0.0049
52	1e+13	NDD unbiased	2.026	2.0256	-0.0004
53	1e+13	NDD unbiased	2.0473	2.0426	-0.0047

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.9273	1.9378	1.9483	0.014849	1.9808	1.9958	2.0109	0.021284	0.0535	0.05805	0.0626	0.0064347
1e+12	1.9373	1.9677	1.9785	0.020258	1.9362	1.9657	1.9771	0.019769	-0.0409	-0.001925	0.0391	0.032733
5e+12	1.9158	1.9557	2.0015	0.041171	1.9154	1.9485	1.9789	0.034981	-0.0226	-0.007175	-0.0004	0.01054
1e+13	1.8347	1.9867	2.0473	0.10171	1.8298	1.9829	2.0426	0.10232	-0.0051	-0.003775	-0.0004	0.0022559

Device Test: 107.2 I_PGOOD_PD_RES(_PGOOD Internal Resistance VIN_14V)


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

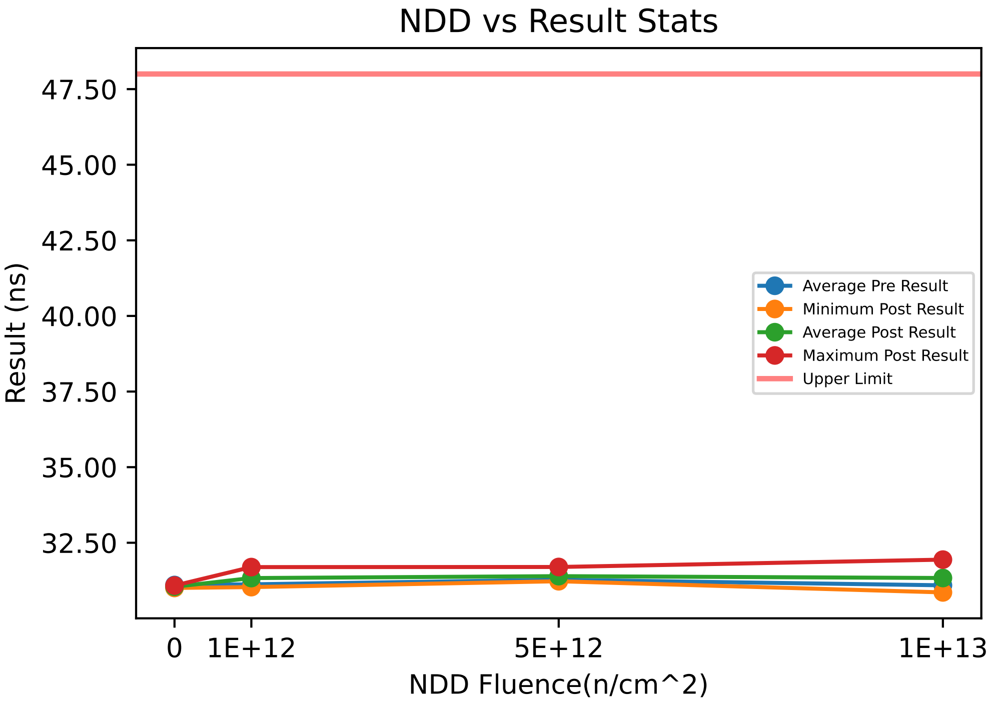
Test Results (Lower Limit = 0.7, Upper Limit = 1.9 (Mohm))

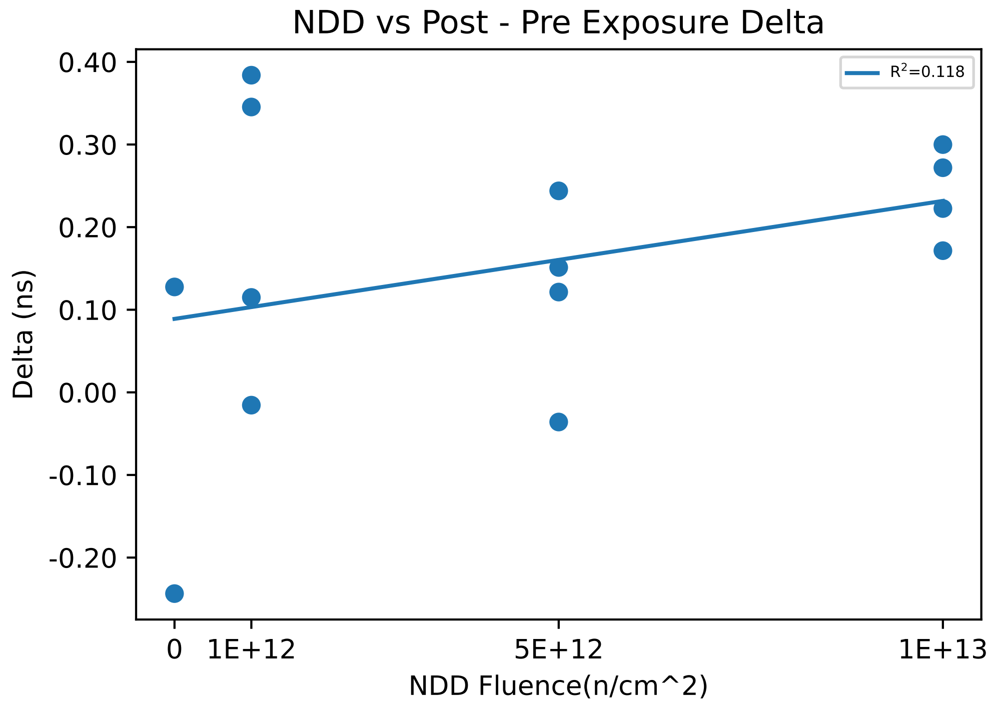
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	1.0692	0.9971	-0.0721
2	0	Correlation	1.0575	0.9961	-0.0614
30	1e+12	NDD unbiased	1.0716	1.0578	-0.0138
31	1e+12	NDD unbiased	1.0589	1.0733	0.0144
32	1e+12	NDD unbiased	1.0637	1.0634	-0.0003
33	1e+12	NDD unbiased	1.092	1.0849	-0.0071
44	5e+12	NDD unbiased	1.078	1.0823	0.0043
45	5e+12	NDD unbiased	1.0721	1.0539	-0.0182
46	5e+12	NDD unbiased	1.0847	1.0871	0.0024
47	5e+12	NDD unbiased	1.0562	1.0597	0.0035
50	1e+13	NDD unbiased	1.0681	1.0636	-0.0045
51	1e+13	NDD unbiased	1.0502	1.0527	0.0025
52	1e+13	NDD unbiased	1.0671	1.0603	-0.0068
53	1e+13	NDD unbiased	1.0658	1.0556	-0.0102

Test Statistics (Mohm)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.0575	1.0634	1.0692	0.0082731	0.9961	0.9966	0.9971	0.00070711	-0.0721	-0.06675	-0.0614	0.007566
1e+12	1.0589	1.0716	1.092	0.014604	1.0578	1.0698	1.0849	0.011905	-0.0138	-0.0017	0.0144	0.012066
5e+12	1.0562	1.0728	1.0847	0.012175	1.0539	1.0708	1.0871	0.016399	-0.0182	-0.002	0.0043	0.010828
1e+13	1.0502	1.0628	1.0681	0.0084526	1.0527	1.0581	1.0636	0.0048473	-0.0102	-0.00475	0.0025	0.0053706

Device Test: 110.0 SW_T_LPHL_PWM(_Prop Delay LO Off PWM VIN_10V)





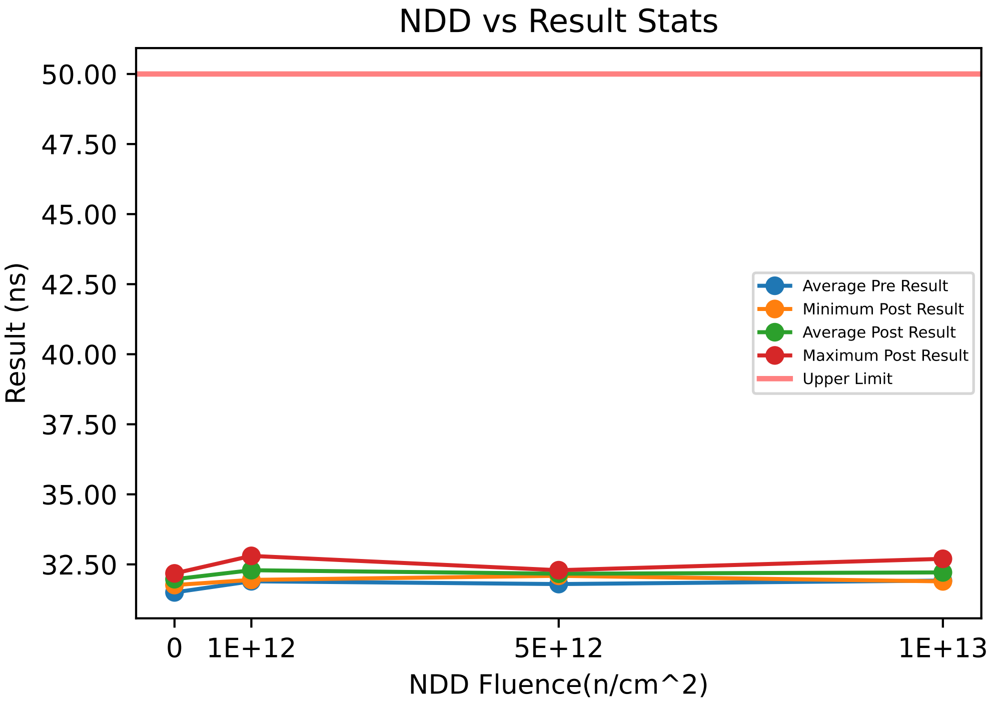
Test Results (Upper Limit = 48.0 (ns))

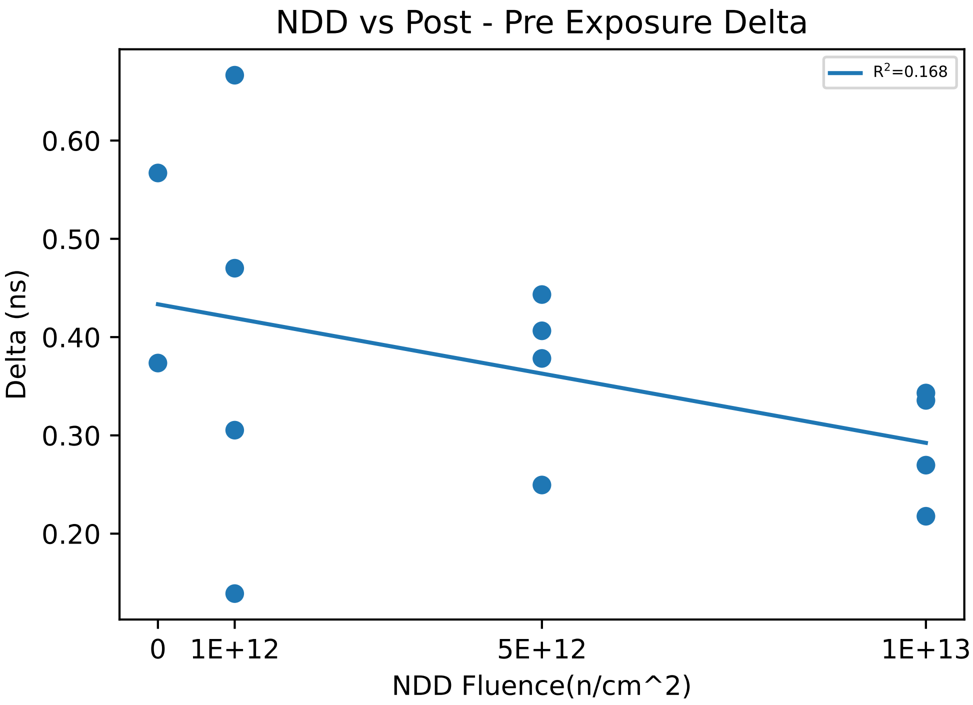
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	30.957	31.084	0.1276
2	0	Correlation	31.25	31.006	-0.2436
30	1e+12	NDD unbiased	30.873	31.257	0.3839
31	1e+12	NDD unbiased	31.049	31.034	-0.0155
32	1e+12	NDD unbiased	31.231	31.346	0.1149
33	1e+12	NDD unbiased	31.35	31.695	0.3454
44	5e+12	NDD unbiased	31.548	31.699	0.1512
45	5e+12	NDD unbiased	31.288	31.252	-0.0359
46	5e+12	NDD unbiased	31.162	31.406	0.2439
47	5e+12	NDD unbiased	31.106	31.228	0.1214
50	1e+13	NDD unbiased	31.642	31.942	0.2999
51	1e+13	NDD unbiased	30.687	30.859	0.1715
52	1e+13	NDD unbiased	31.128	31.35	0.2225
53	1e+13	NDD unbiased	30.916	31.188	0.2719

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	30.957	31.103	31.25	0.20704	31.006	31.045	31.084	0.055437	-0.2436	-0.058	0.1276	0.26248
1e+12	30.873	31.126	31.35	0.2091	31.034	31.333	31.695	0.27491	-0.0155	0.20718	0.3839	0.19012
5e+12	31.106	31.276	31.548	0.1966	31.228	31.396	31.699	0.21691	-0.0359	0.12015	0.2439	0.11638
1e+13	30.687	31.093	31.642	0.4077	30.859	31.335	31.942	0.45356	0.1715	0.24145	0.2999	0.056556

Device Test: 110.1 SW_T_HPHL_PWM(_Prop Delay HO Off PWM VIN_10V)


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

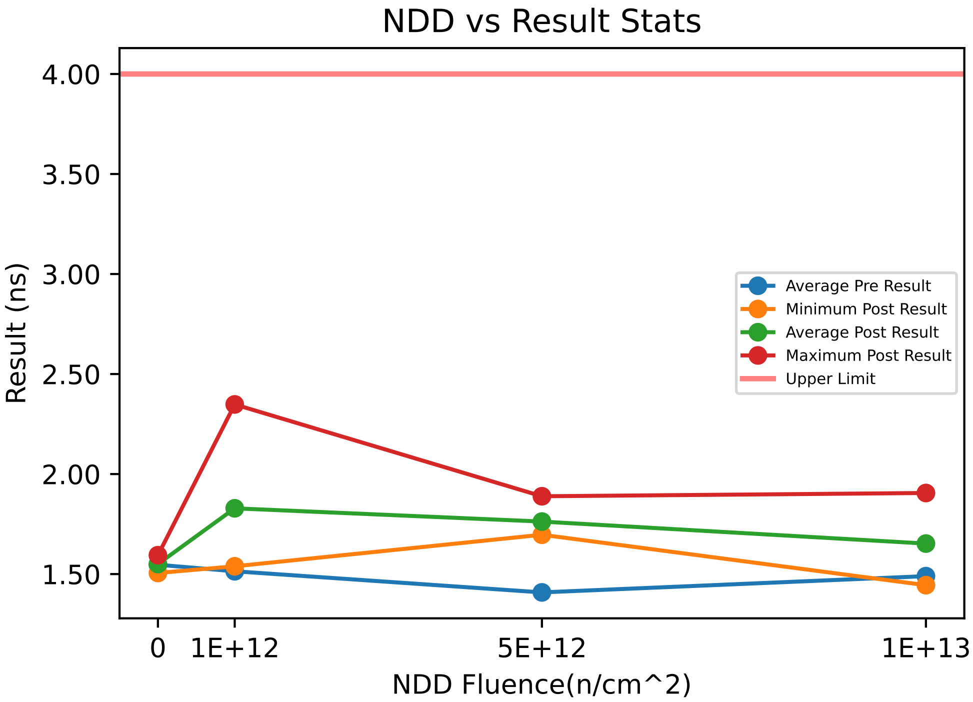
Test Results (Upper Limit = 50.0 (ns))

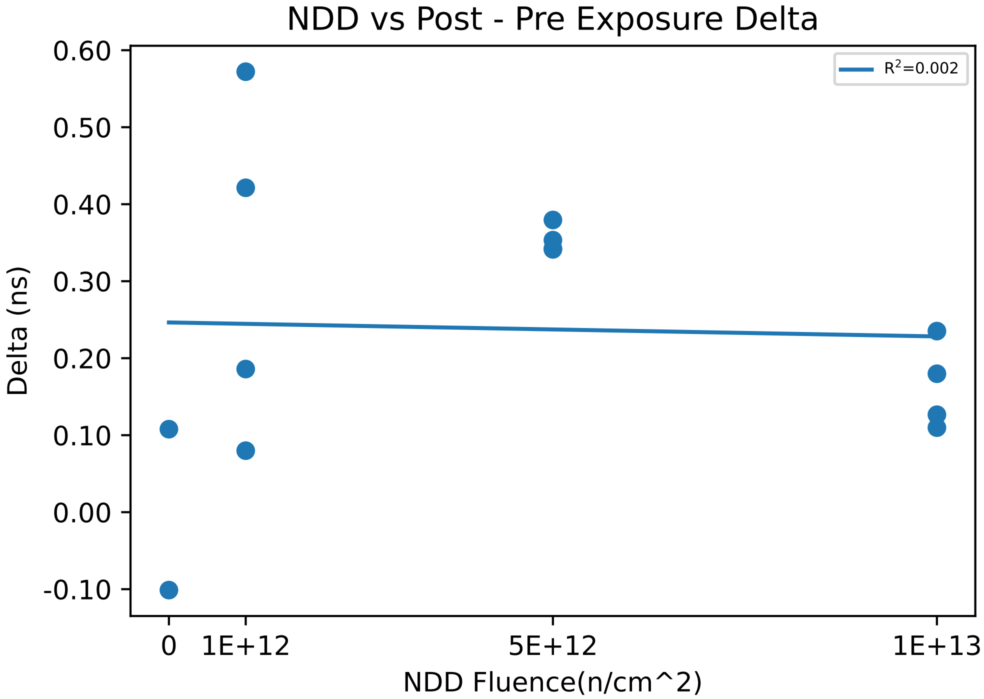
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	31.389	31.763	0.3736
2	0	Correlation	31.611	32.178	0.567
30	1e+12	NDD unbiased	31.524	32.191	0.6665
31	1e+12	NDD unbiased	31.808	31.947	0.139
32	1e+12	NDD unbiased	32.333	32.803	0.4701
33	1e+12	NDD unbiased	31.921	32.226	0.3053
44	5e+12	NDD unbiased	31.745	32.188	0.4433
45	5e+12	NDD unbiased	31.847	32.097	0.2495
46	5e+12	NDD unbiased	31.914	32.292	0.3783
47	5e+12	NDD unbiased	31.685	32.092	0.4064
50	1e+13	NDD unbiased	32.355	32.698	0.3431
51	1e+13	NDD unbiased	31.558	31.893	0.3356
52	1e+13	NDD unbiased	32.044	32.261	0.2177
53	1e+13	NDD unbiased	31.731	32.001	0.2697

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	31.389	31.5	31.611	0.15719	31.763	31.97	32.178	0.29394	0.3736	0.4703	0.567	0.13675
1e+12	31.524	31.897	32.333	0.33556	31.947	32.292	32.803	0.36306	0.139	0.39522	0.6665	0.22578
5e+12	31.685	31.798	31.914	0.10235	32.092	32.167	32.292	0.094332	0.2495	0.36937	0.4433	0.084233
1e+13	31.558	31.922	32.355	0.35187	31.893	32.213	32.698	0.35818	0.2177	0.29153	0.3431	0.059243

Device Test: 110.11 SW_T_MATCH_OFF(_Delay Match LO Off HO On IIM Interlock VIN_10V)





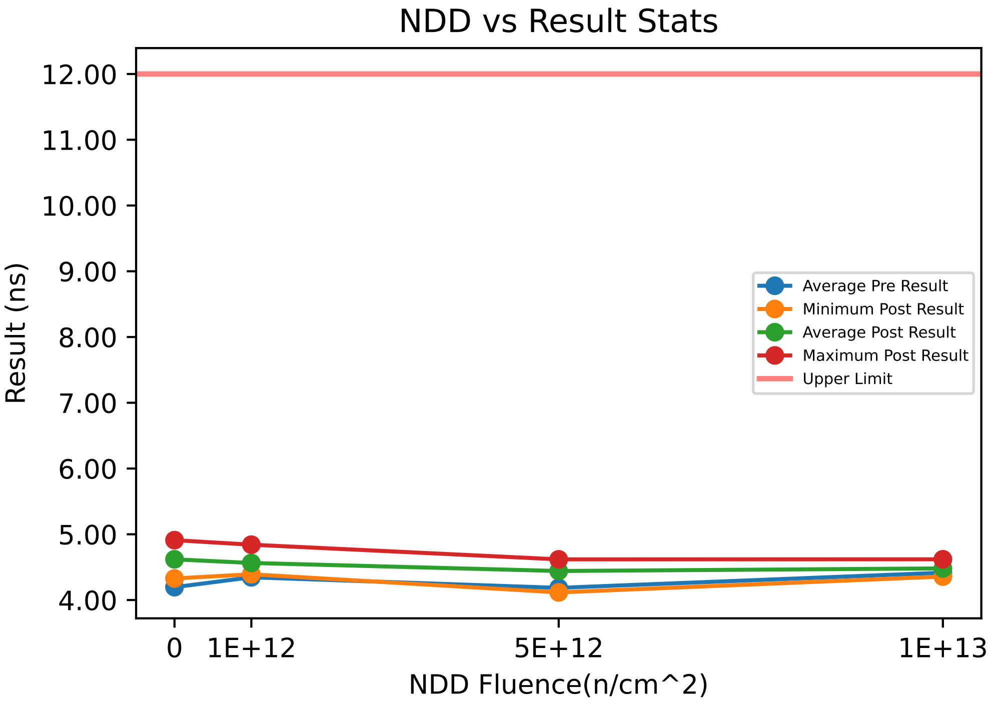
Test Results (Upper Limit = 4.0 (ns))

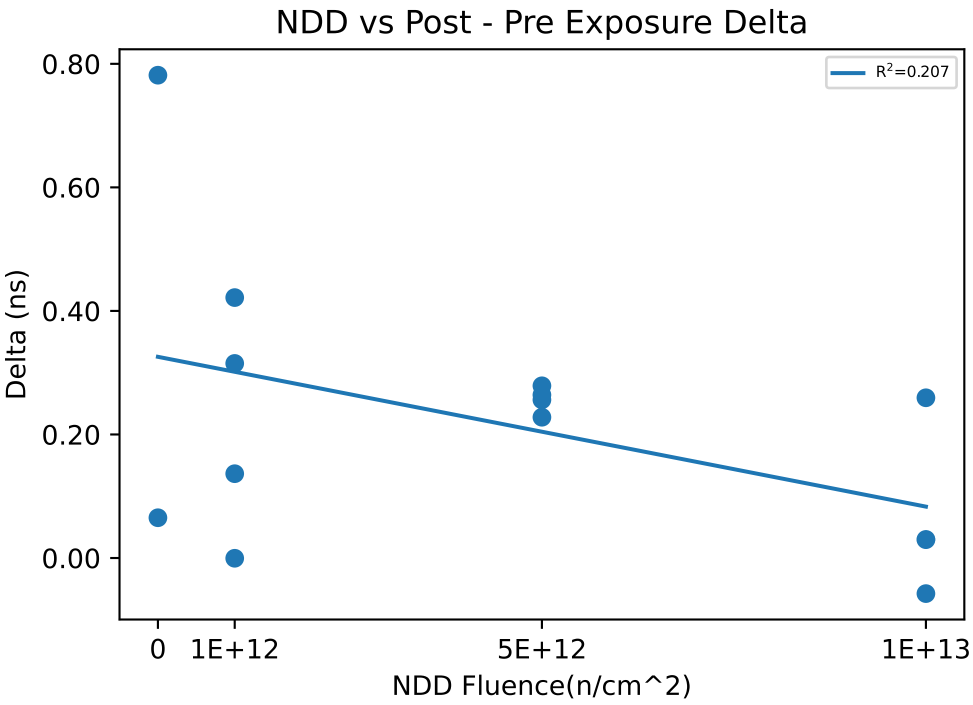
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	1.3977	1.5055	0.1078
2	0	Correlation	1.6956	1.5944	-0.1012
30	1e+12	NDD unbiased	1.2366	1.8087	0.5721
31	1e+12	NDD unbiased	1.459	1.5389	0.0799
32	1e+12	NDD unbiased	1.1982	1.6195	0.4213
33	1e+12	NDD unbiased	2.1622	2.3481	0.1859
44	5e+12	NDD unbiased	1.5477	1.889	0.3413
45	5e+12	NDD unbiased	1.3948	1.7372	0.3424
46	5e+12	NDD unbiased	1.3433	1.6966	0.3533
47	5e+12	NDD unbiased	1.3478	1.7273	0.3795
50	1e+13	NDD unbiased	1.7787	1.9053	0.1266
51	1e+13	NDD unbiased	1.2093	1.4445	0.2352
52	1e+13	NDD unbiased	1.5467	1.7265	0.1798
53	1e+13	NDD unbiased	1.424	1.5338	0.1098

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.3977	1.5467	1.6956	0.21065	1.5055	1.5499	1.5944	0.062862	-0.1012	0.0033	0.1078	0.14779
1e+12	1.1982	1.514	2.1622	0.44716	1.5389	1.8288	2.3481	0.3642	0.0799	0.3148	0.5721	0.22311
5e+12	1.3433	1.4084	1.5477	0.095742	1.6966	1.7625	1.889	0.08607	0.3413	0.35413	0.3795	0.017763
1e+13	1.2093	1.4897	1.7787	0.23784	1.4445	1.6525	1.9053	0.20554	0.1098	0.16285	0.2352	0.056716

Device Test: 110.12 SW_T_MATCH_ON(_Delay Match LO On HO Off IIM Interlock Disable VIN_10V)


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

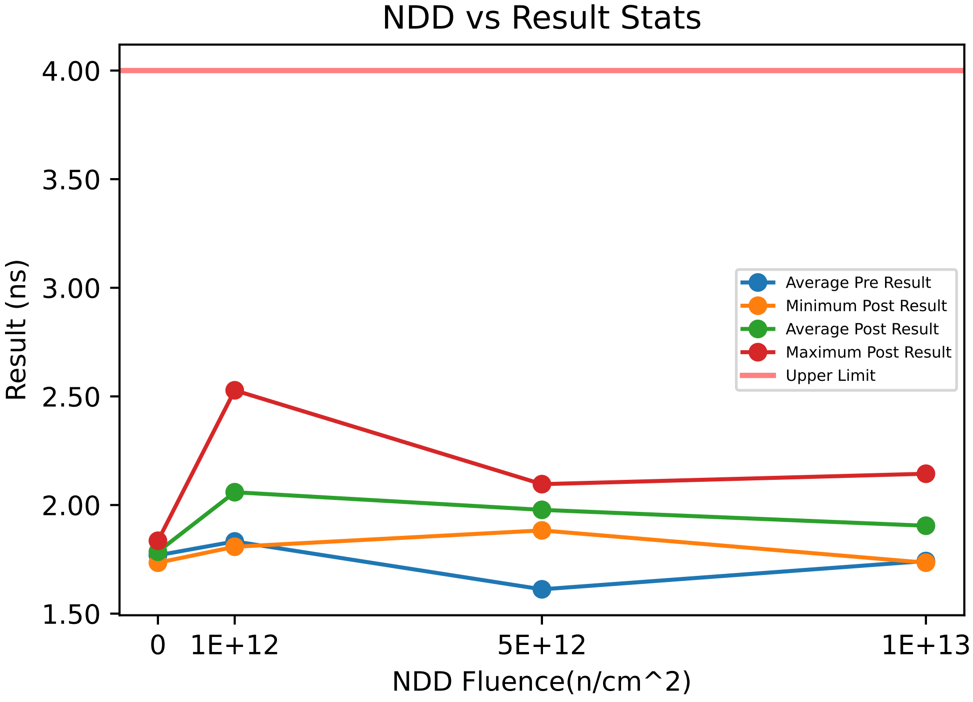
Test Results (Upper Limit = 12.0 (ns))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	4.2625	4.3277	0.0652
2	0	Correlation	4.129	4.9106	0.7816
30	1e+12	NDD unbiased	4.1913	4.6129	0.4216
31	1e+12	NDD unbiased	4.3922	4.3918	-0.0004
32	1e+12	NDD unbiased	4.5267	4.8417	0.315
33	1e+12	NDD unbiased	4.2722	4.4087	0.1365
44	5e+12	NDD unbiased	3.86	4.1161	0.2561
45	5e+12	NDD unbiased	4.2452	4.524	0.2788
46	5e+12	NDD unbiased	4.3546	4.6186	0.264
47	5e+12	NDD unbiased	4.2801	4.508	0.2279
50	1e+13	NDD unbiased	4.6773	4.6197	-0.0576
51	1e+13	NDD unbiased	4.1885	4.4479	0.2594
52	1e+13	NDD unbiased	4.4694	4.4995	0.0301
53	1e+13	NDD unbiased	4.327	4.3567	0.0297

Test Statistics (ns)

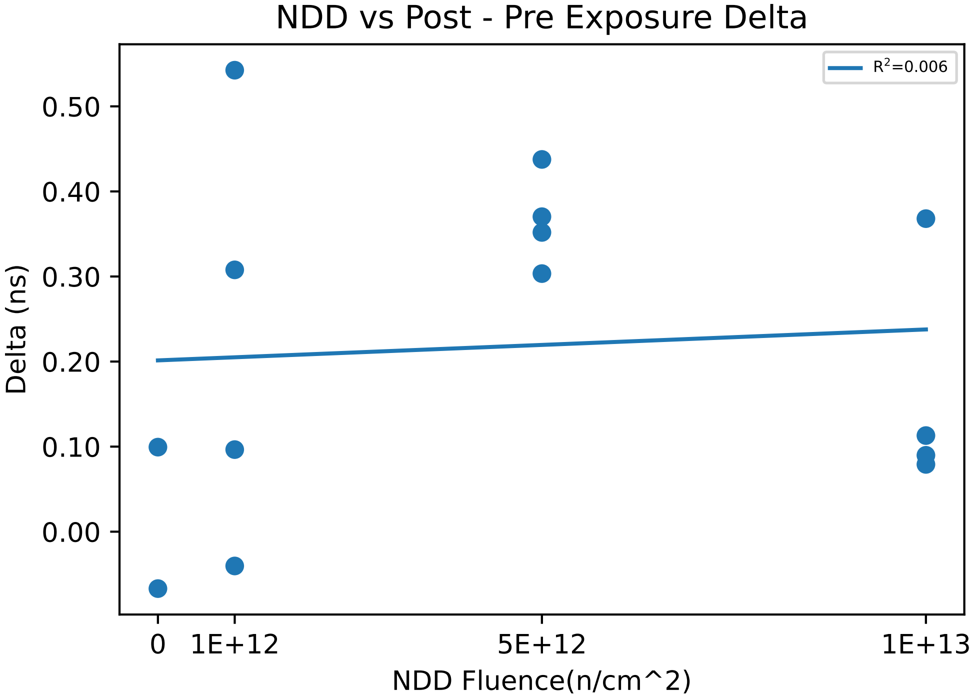
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.129	4.1958	4.2625	0.094399	4.3277	4.6191	4.9106	0.41217	0.0652	0.4234	0.7816	0.50657
1e+12	4.1913	4.3456	4.5267	0.14625	4.3918	4.5638	4.8417	0.21078	-0.0004	0.21818	0.4216	0.18726
5e+12	3.86	4.185	4.3546	0.2214	4.1161	4.4417	4.6186	0.22247	0.2279	0.2567	0.2788	0.021381
1e+13	4.1885	4.4155	4.6773	0.20881	4.3567	4.4809	4.6197	0.10974	-0.0576	0.0654	0.2594	0.13575

Device Test: 110.13 SW_T_MATCH_OFF(_Delay Match LO Off HO On IIM Interlock Disable VIN_10V)



Test Results (Upper Limit = 4.0 (ns))

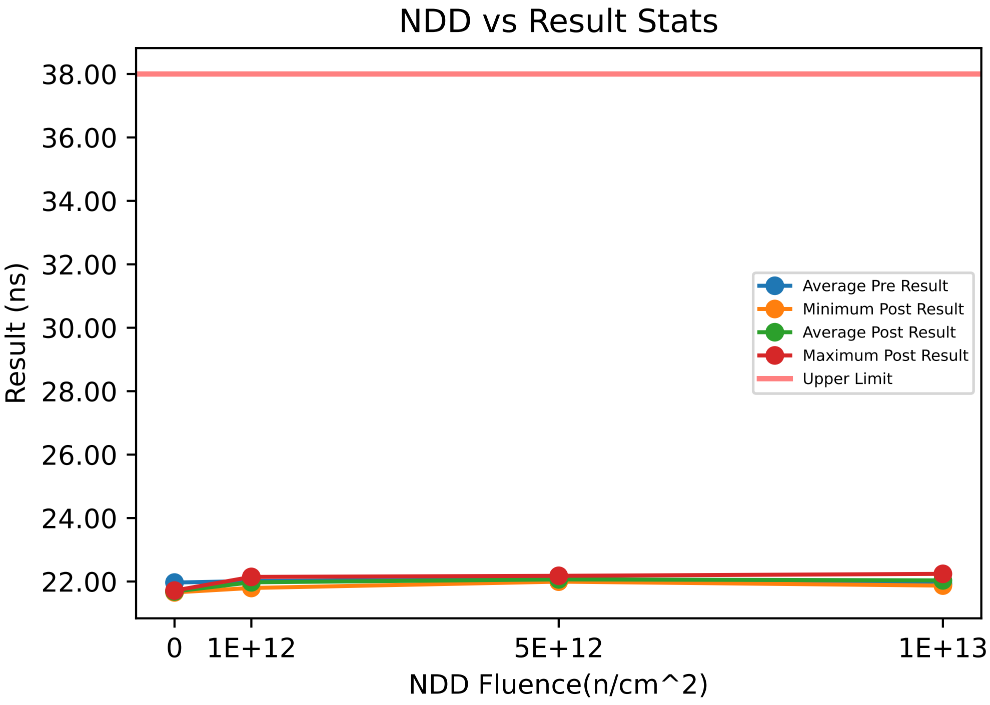
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	1.635	1.7344	0.0994
2	0	Correlation	1.9023	1.8354	-0.0669
30	1e+12	NDD unbiased	1.5094	2.0519	0.5425
31	1e+12	NDD unbiased	1.8482	1.8079	-0.0403
32	1e+12	NDD unbiased	1.5403	1.8481	0.3078
33	1e+12	NDD unbiased	2.4316	2.5281	0.0965
44	5e+12	NDD unbiased	1.6585	2.0961	0.4376
45	5e+12	NDD unbiased	1.6691	1.9725	0.3034
46	5e+12	NDD unbiased	1.5314	1.8832	0.3518
47	5e+12	NDD unbiased	1.5889	1.9592	0.3703
50	1e+13	NDD unbiased	2.0649	2.144	0.0791
51	1e+13	NDD unbiased	1.3666	1.7346	0.368
52	1e+13	NDD unbiased	1.8678	1.9576	0.0898
53	1e+13	NDD unbiased	1.6693	1.7823	0.113

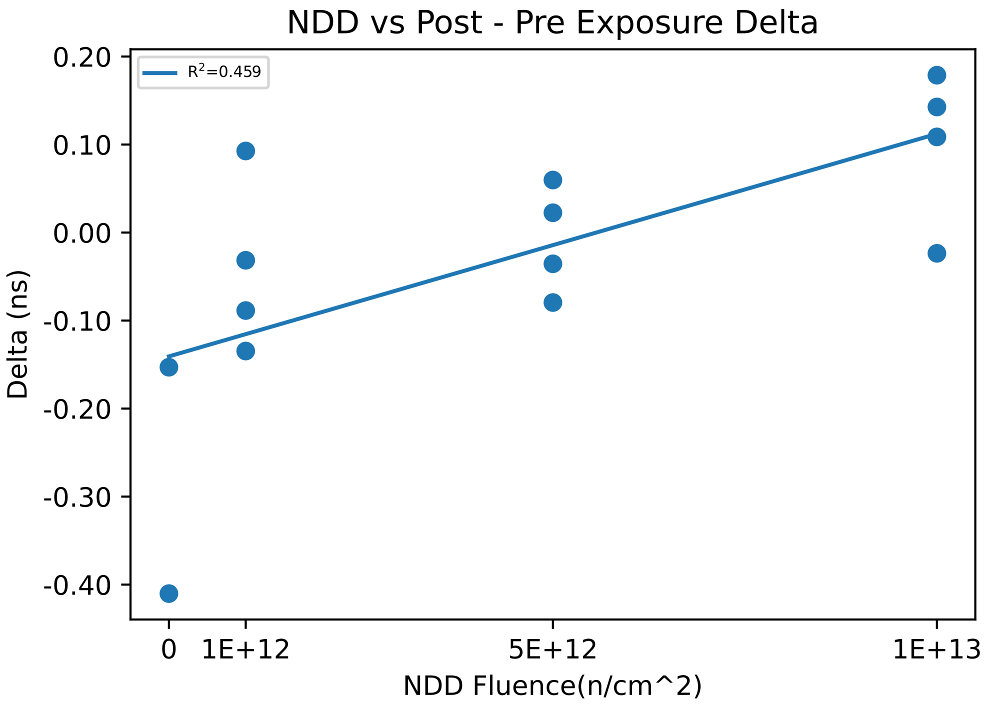


Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.635	1.7687	1.9023	0.18901	1.7344	1.7849	1.8354	0.071418	-0.0669	0.01625	0.0994	0.11759
1e+12	1.5094	1.8324	2.4316	0.42776	1.8079	2.059	2.5281	0.33047	-0.0403	0.22662	0.5425	0.25466
5e+12	1.5314	1.612	1.6691	0.064427	1.8832	1.9777	2.0961	0.088163	0.3034	0.36577	0.4376	0.055574
1e+13	1.3666	1.7422	2.0649	0.29794	1.7346	1.9046	2.144	0.18617	0.0791	0.16247	0.368	0.13775

Device Test: 110.2 SW_T_LPLH_IIM(_Prop Delay LO On IIM Interlock VIN_10V)





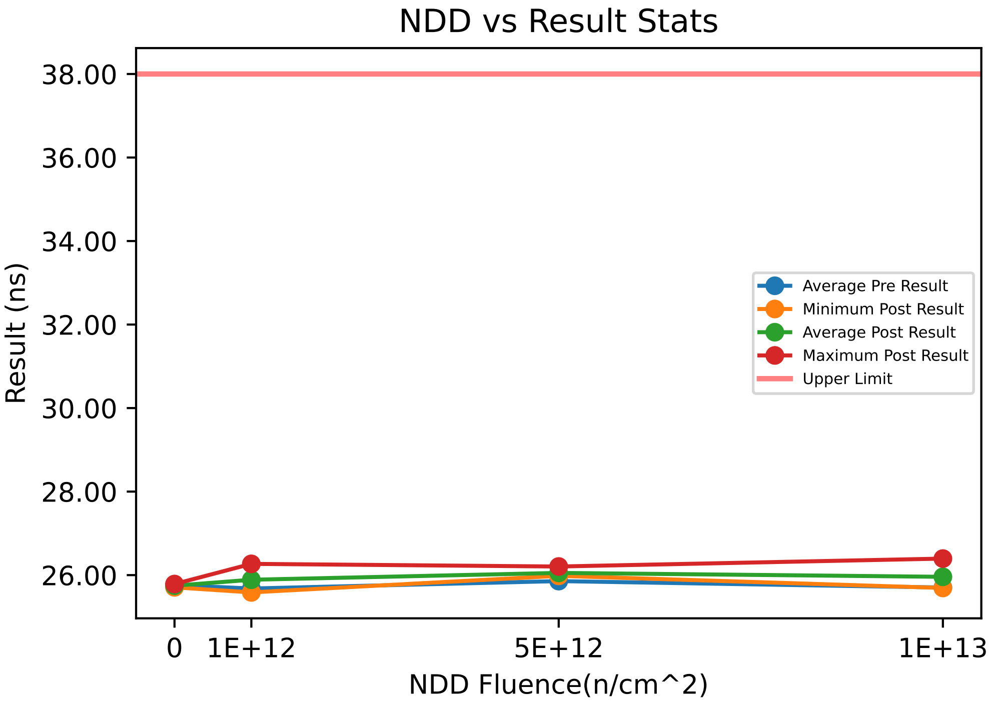
Test Results (Upper Limit = 38.0 (ns))

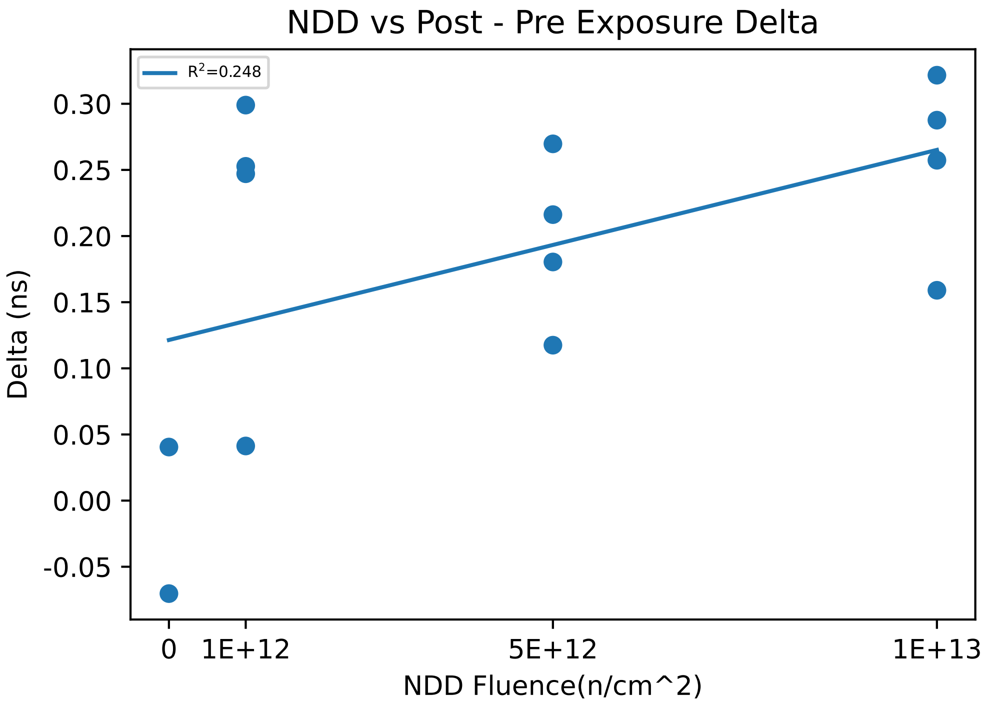
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	21.868	21.715	-0.153
2	0	Correlation	22.067	21.657	-0.4102
30	1e+12	NDD unbiased	21.87	21.839	-0.0315
31	1e+12	NDD unbiased	21.931	21.796	-0.1346
32	1e+12	NDD unbiased	22.234	22.145	-0.0886
33	1e+12	NDD unbiased	22.023	22.116	0.0927
44	5e+12	NDD unbiased	22.259	22.179	-0.0795
45	5e+12	NDD unbiased	21.969	22.028	0.0597
46	5e+12	NDD unbiased	22.031	21.995	-0.0355
47	5e+12	NDD unbiased	22.042	22.064	0.0225
50	1e+13	NDD unbiased	22.098	22.241	0.1427
51	1e+13	NDD unbiased	21.895	21.871	-0.0236
52	1e+13	NDD unbiased	22.033	22.141	0.1087
53	1e+13	NDD unbiased	21.709	21.888	0.1788

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	21.868	21.967	22.067	0.14078	21.657	21.686	21.715	0.041083	-0.4102	-0.2816	-0.153	0.18187
1e+12	21.87	22.015	22.234	0.15909	21.796	21.974	22.145	0.182	-0.1346	-0.0405	0.0927	0.098305
5e+12	21.969	22.075	22.259	0.12667	21.995	22.067	22.179	0.080074	-0.0795	-0.0082	0.0597	0.061595
1e+13	21.709	21.934	22.098	0.1721	21.871	22.035	22.241	0.18466	-0.0236	0.10165	0.1788	0.088269

Device Test: 110.3 SW_T_LPHL_IIM(_Prop Delay LO Off IIM Interlock VIN_10V)





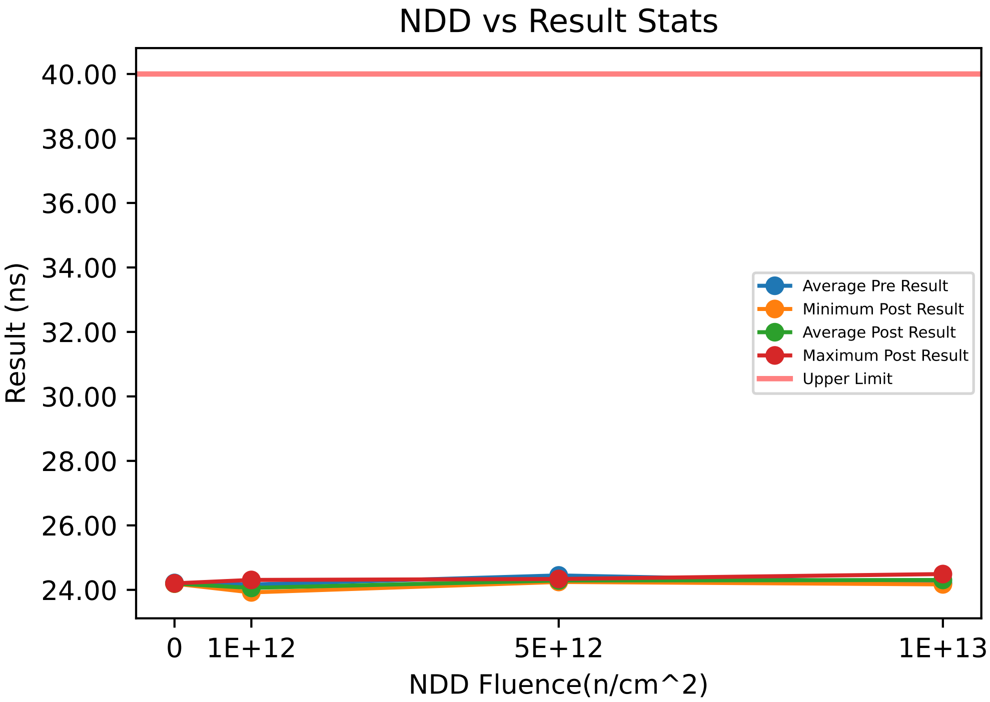
Test Results (Upper Limit = 38.0 (ns))

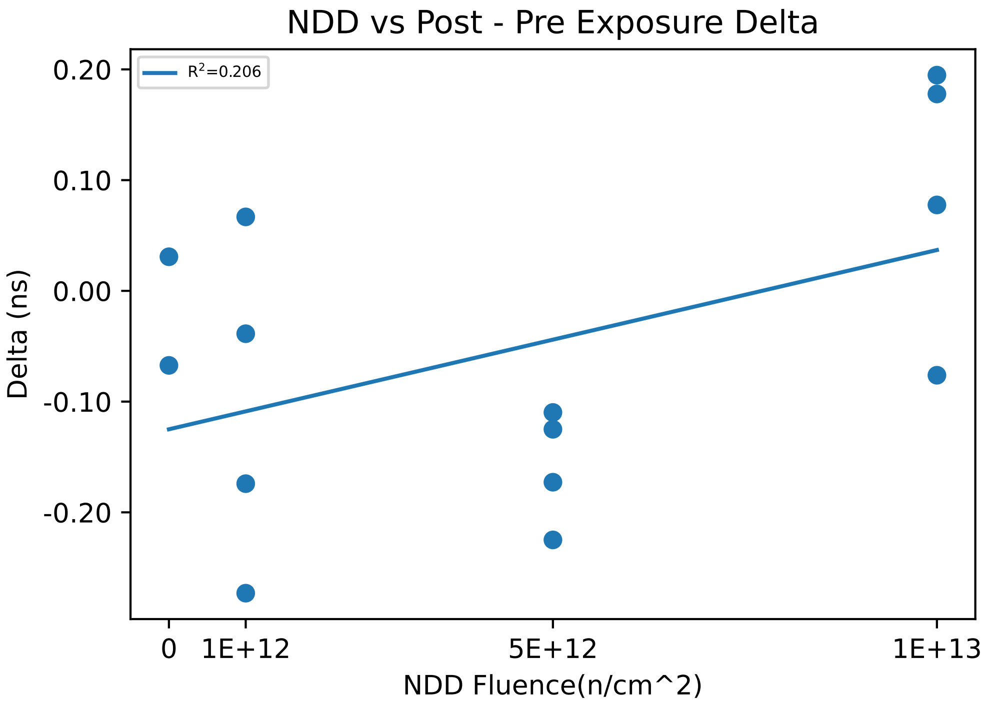
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	25.667	25.707	0.0405
2	0	Correlation	25.856	25.786	-0.0703
30	1e+12	NDD unbiased	25.474	25.773	0.299
31	1e+12	NDD unbiased	25.545	25.586	0.0413
32	1e+12	NDD unbiased	25.68	25.927	0.2471
33	1e+12	NDD unbiased	26.017	26.269	0.2527
44	5e+12	NDD unbiased	25.99	26.206	0.2162
45	5e+12	NDD unbiased	25.865	25.982	0.1175
46	5e+12	NDD unbiased	25.853	26.034	0.1804
47	5e+12	NDD unbiased	25.719	25.989	0.2697
50	1e+13	NDD unbiased	26.074	26.395	0.3216
51	1e+13	NDD unbiased	25.534	25.692	0.159
52	1e+13	NDD unbiased	25.788	26.045	0.2573
53	1e+13	NDD unbiased	25.416	25.703	0.2876

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	25.667	25.761	25.856	0.13407	25.707	25.747	25.786	0.05572	-0.0703	-0.0149	0.0405	0.078347
1e+12	25.474	25.679	26.017	0.24086	25.586	25.889	26.269	0.28946	0.0413	0.21002	0.299	0.11486
5e+12	25.719	25.857	25.99	0.11068	25.982	26.053	26.206	0.10477	0.1175	0.19595	0.2697	0.063889
1e+13	25.416	25.703	26.074	0.29209	25.692	25.959	26.395	0.33381	0.159	0.25637	0.3216	0.070029

Device Test: 110.4 SW_T_HPLH_IIM(_Prop Delay HO On IIM Interlock VIN_10V)





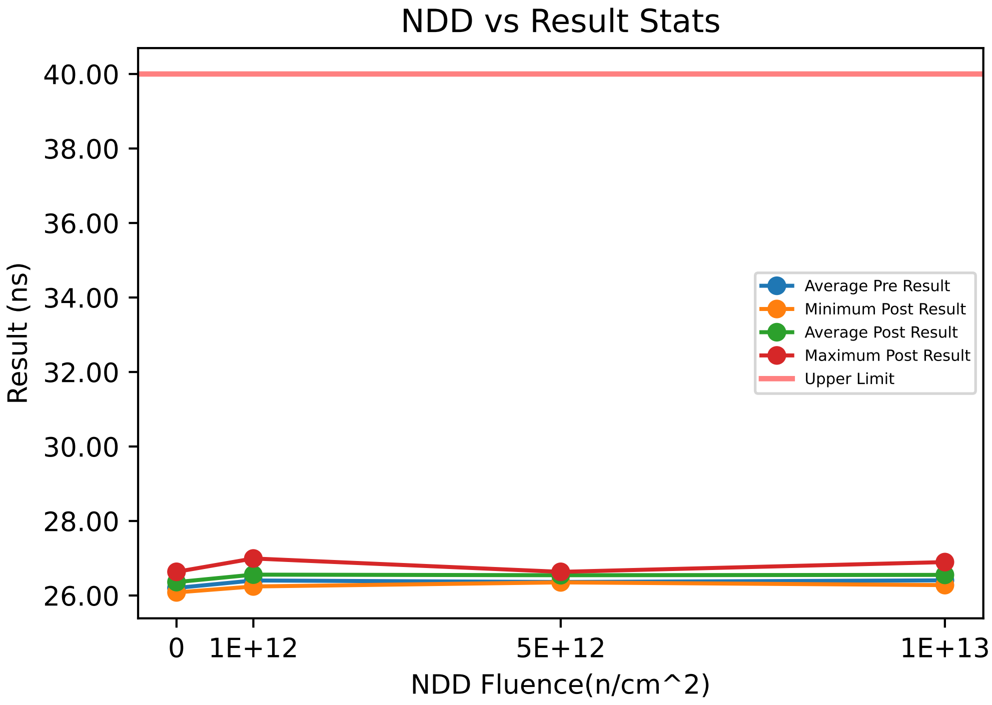
Test Results (Upper Limit = 40.0 (ns))

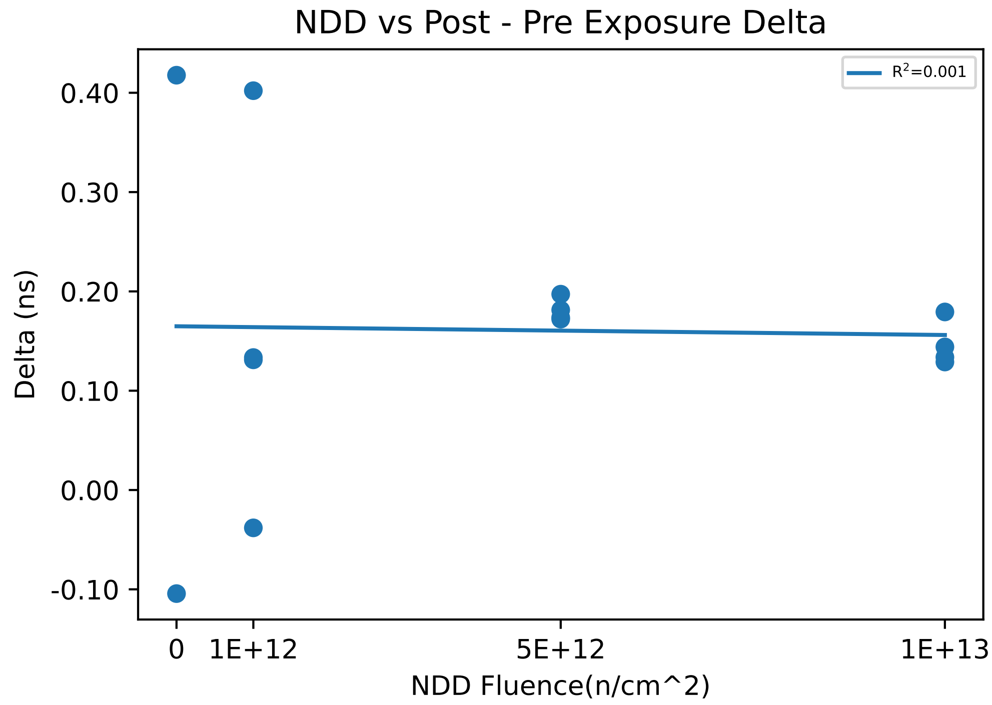
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	24.269	24.202	-0.0673
2	0	Correlation	24.161	24.192	0.0308
30	1e+12	NDD unbiased	24.237	23.964	-0.273
31	1e+12	NDD unbiased	24.086	24.047	-0.0387
32	1e+12	NDD unbiased	24.482	24.308	-0.1741
33	1e+12	NDD unbiased	23.854	23.921	0.0668
44	5e+12	NDD unbiased	24.442	24.317	-0.125
45	5e+12	NDD unbiased	24.47	24.245	-0.2249
46	5e+12	NDD unbiased	24.51	24.337	-0.1728
47	5e+12	NDD unbiased	24.371	24.261	-0.1098
50	1e+13	NDD unbiased	24.295	24.49	0.1948
51	1e+13	NDD unbiased	24.324	24.248	-0.0762
52	1e+13	NDD unbiased	24.241	24.319	0.0776
53	1e+13	NDD unbiased	23.992	24.17	0.1778

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	24.161	24.215	24.269	0.07658	24.192	24.197	24.202	0.0072125	-0.0673	-0.01825	0.0308	0.069367
1e+12	23.854	24.165	24.482	0.2636	23.921	24.06	24.308	0.17325	-0.273	-0.10475	0.0668	0.14934
5e+12	24.371	24.448	24.51	0.058435	24.245	24.29	24.337	0.043953	-0.2249	-0.15812	-0.1098	0.051983
1e+13	23.992	24.213	24.324	0.15146	24.17	24.307	24.49	0.13662	-0.0762	0.0935	0.1948	0.12439

Device Test: 110.5 SW_T_HPHL_IIM(_Prop Delay HO Off IIM Interlock VIN_10V)





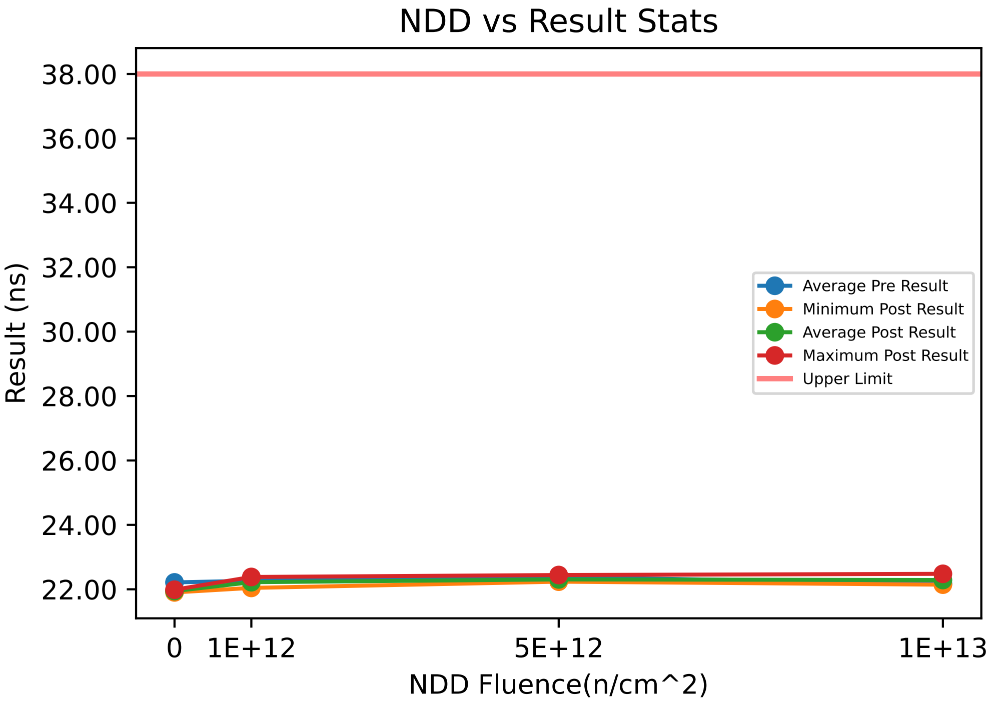
Test Results (Upper Limit = 40.0 (ns))

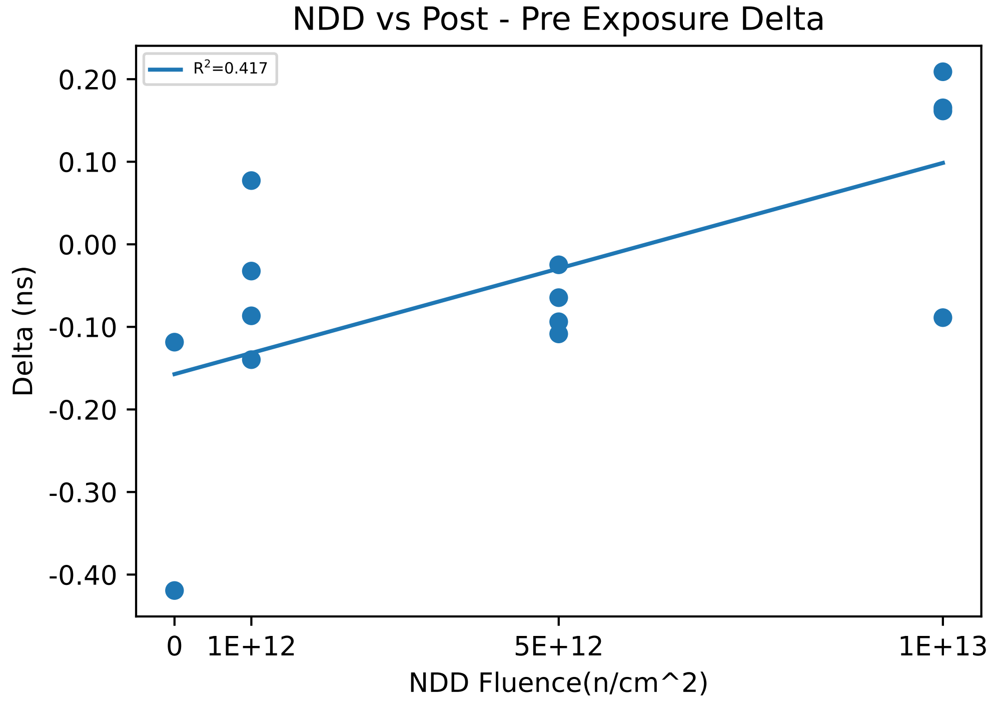
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	26.188	26.083	-0.1043
2	0	Correlation	26.218	26.636	0.4177
30	1e+12	NDD unbiased	26.078	26.48	0.4021
31	1e+12	NDD unbiased	26.281	26.243	-0.0381
32	1e+12	NDD unbiased	26.863	26.994	0.1311
33	1e+12	NDD unbiased	26.39	26.524	0.1334
44	5e+12	NDD unbiased	26.18	26.352	0.1721
45	5e+12	NDD unbiased	26.417	26.598	0.1813
46	5e+12	NDD unbiased	26.438	26.635	0.1972
47	5e+12	NDD unbiased	26.418	26.592	0.1737
50	1e+13	NDD unbiased	26.768	26.897	0.1289
51	1e+13	NDD unbiased	26.265	26.399	0.1337
52	1e+13	NDD unbiased	26.459	26.638	0.1793
53	1e+13	NDD unbiased	26.135	26.279	0.1441

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	26.188	26.203	26.218	0.021425	26.083	26.359	26.636	0.39054	-0.1043	0.1567	0.4177	0.36911
1e+12	26.078	26.403	26.863	0.33278	26.243	26.56	26.994	0.3145	-0.0381	0.15713	0.4021	0.18199
5e+12	26.18	26.363	26.438	0.12252	26.352	26.544	26.635	0.12954	0.1721	0.18107	0.1972	0.011475
1e+13	26.135	26.407	26.768	0.27511	26.279	26.553	26.897	0.27339	0.1289	0.1465	0.1793	0.022768

Device Test: 110.6 SW_T_LPLH_IIM(_Prop Delay LO On IIM Interlock Disable VIN_10V)


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

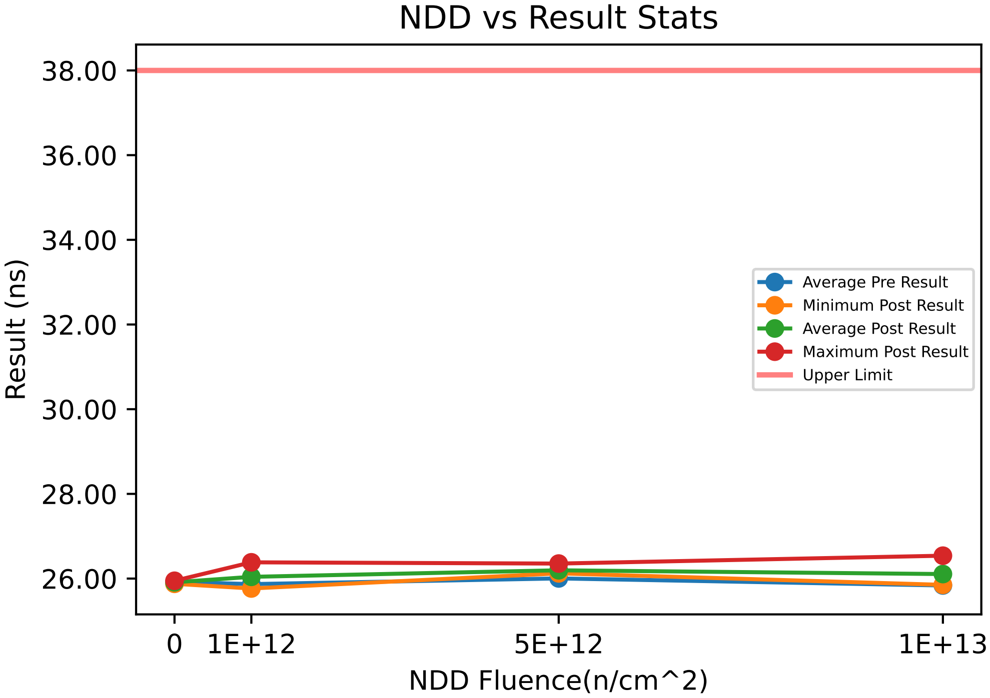
Test Results (Upper Limit = 38.0 (ns))

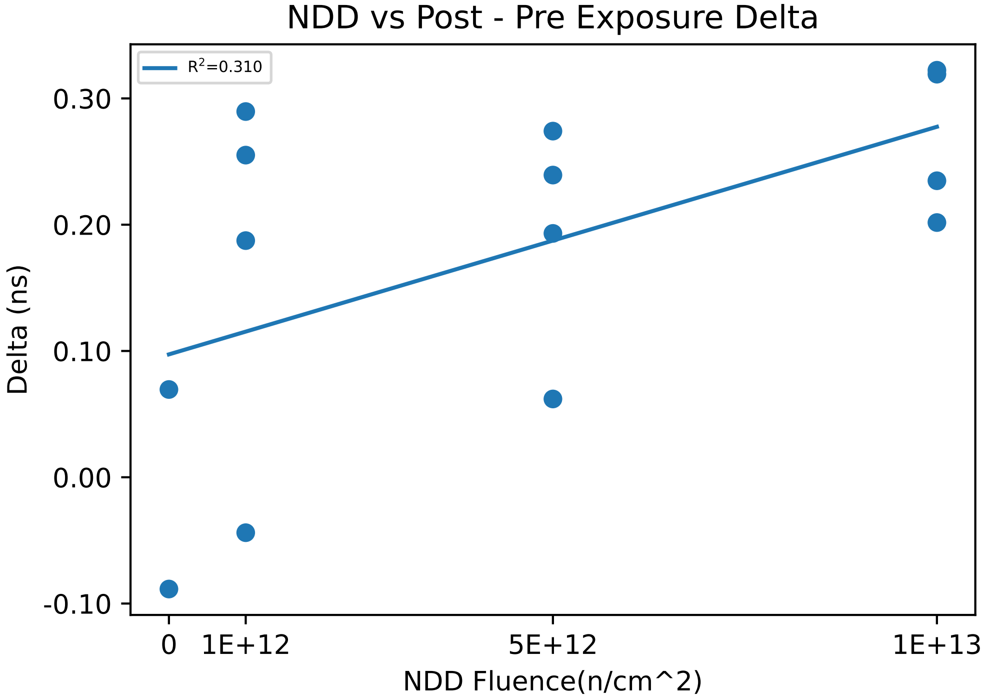
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	22.105	21.986	-0.1185
2	0	Correlation	22.323	21.903	-0.4193
30	1e+12	NDD unbiased	22.121	22.088	-0.0324
31	1e+12	NDD unbiased	22.13	22.043	-0.0866
32	1e+12	NDD unbiased	22.522	22.383	-0.1397
33	1e+12	NDD unbiased	22.288	22.365	0.0772
44	5e+12	NDD unbiased	22.536	22.443	-0.0938
45	5e+12	NDD unbiased	22.302	22.277	-0.0248
46	5e+12	NDD unbiased	22.345	22.237	-0.1085
47	5e+12	NDD unbiased	22.336	22.272	-0.0646
50	1e+13	NDD unbiased	22.271	22.48	0.209
51	1e+13	NDD unbiased	22.233	22.144	-0.0888
52	1e+13	NDD unbiased	22.215	22.381	0.1653
53	1e+13	NDD unbiased	21.985	22.147	0.1615

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	22.105	22.214	22.323	0.15401	21.903	21.945	21.986	0.05869	-0.4193	-0.2689	-0.1185	0.2127
1e+12	22.121	22.265	22.522	0.18772	22.043	22.22	22.383	0.17884	-0.1397	-0.045375	0.0772	0.092718
5e+12	22.302	22.38	22.536	0.10606	22.237	22.307	22.443	0.092211	-0.1085	-0.072925	-0.0248	0.036908
1e+13	21.985	22.176	22.271	0.12916	22.144	22.288	22.48	0.16934	-0.0888	0.11175	0.209	0.13543

Device Test: 110.7 SW_T_LPHL_IIM(_Prop Delay LO Off IIM Interlock Disable VIN_10V)





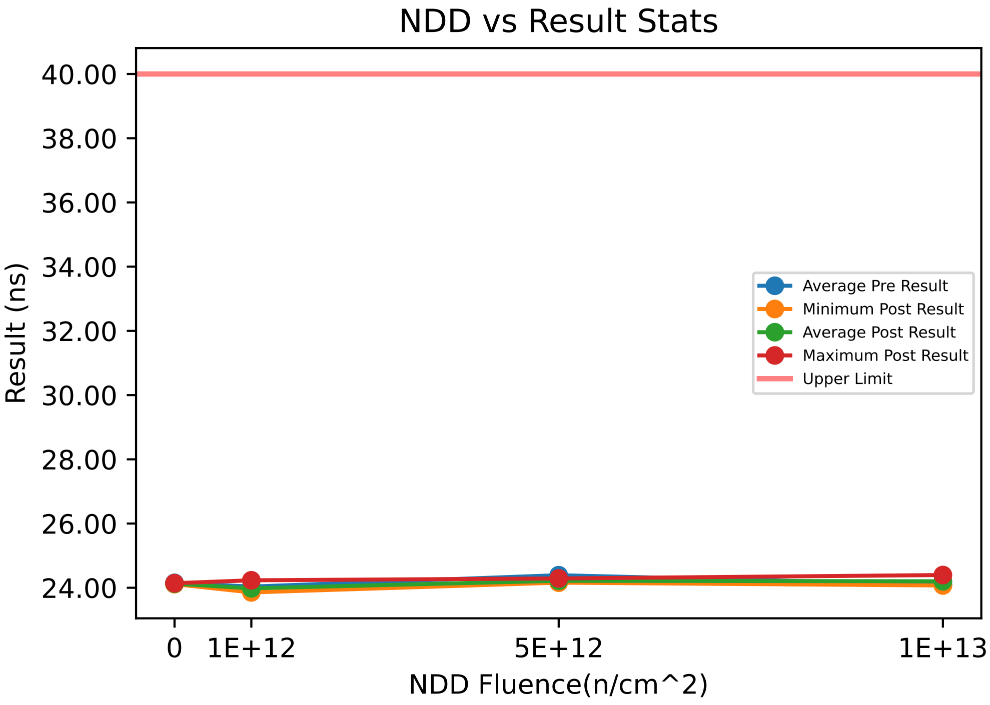
Test Results (Upper Limit = 38.0 (ns))

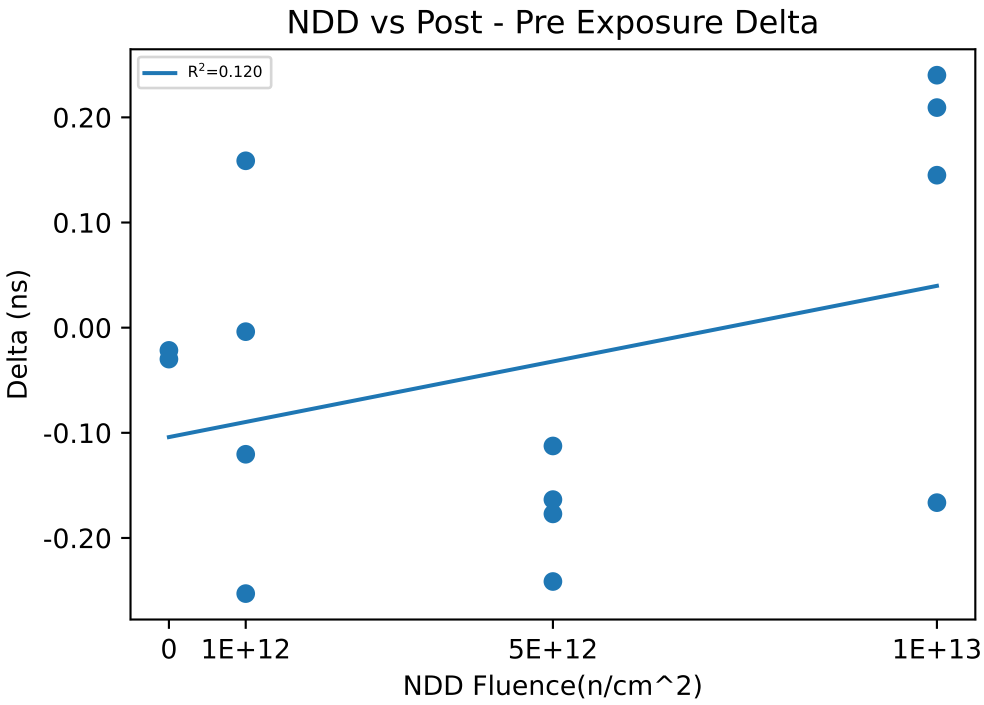
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	25.807	25.876	0.0695
2	0	Correlation	26.036	25.948	-0.0885
30	1e+12	NDD unbiased	25.644	25.934	0.2896
31	1e+12	NDD unbiased	25.81	25.766	-0.0439
32	1e+12	NDD unbiased	25.893	26.081	0.1874
33	1e+12	NDD unbiased	26.129	26.384	0.2551
44	5e+12	NDD unbiased	26.08	26.354	0.2741
45	5e+12	NDD unbiased	26.069	26.131	0.062
46	5e+12	NDD unbiased	25.934	26.173	0.2393
47	5e+12	NDD unbiased	25.93	26.123	0.1931
50	1e+13	NDD unbiased	26.221	26.54	0.3192
51	1e+13	NDD unbiased	25.65	25.852	0.2017
52	1e+13	NDD unbiased	25.946	26.181	0.2348
53	1e+13	NDD unbiased	25.531	25.854	0.3223

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	25.807	25.922	26.036	0.16235	25.876	25.912	25.948	0.050629	-0.0885	-0.0095	0.0695	0.11172
1e+12	25.644	25.869	26.129	0.20164	25.766	26.041	26.384	0.26212	-0.0439	0.17205	0.2896	0.15009
5e+12	25.93	26.003	26.08	0.082352	26.123	26.196	26.354	0.10804	0.062	0.19212	0.2741	0.092878
1e+13	25.531	25.837	26.221	0.30981	25.852	26.107	26.54	0.32795	0.2017	0.2695	0.3223	0.060715

Device Test: 110.8 SW_T_HPLH_IIM(_Prop Delay HO On IIM Interlock Disable VIN_10V)


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

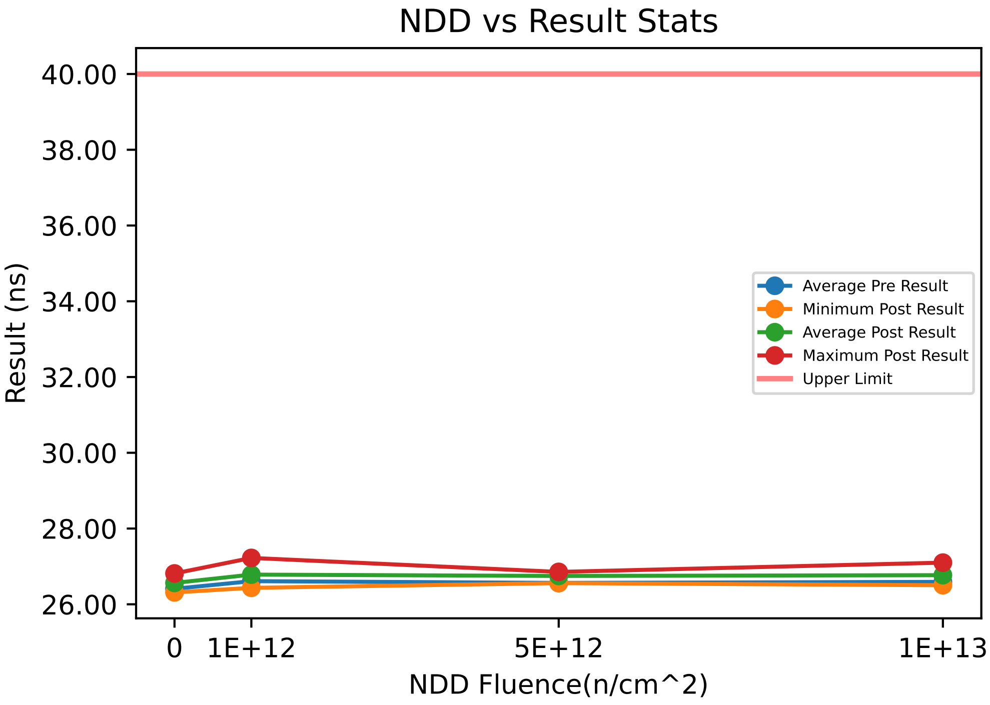
Test Results (Upper Limit = 40.0 (ns))

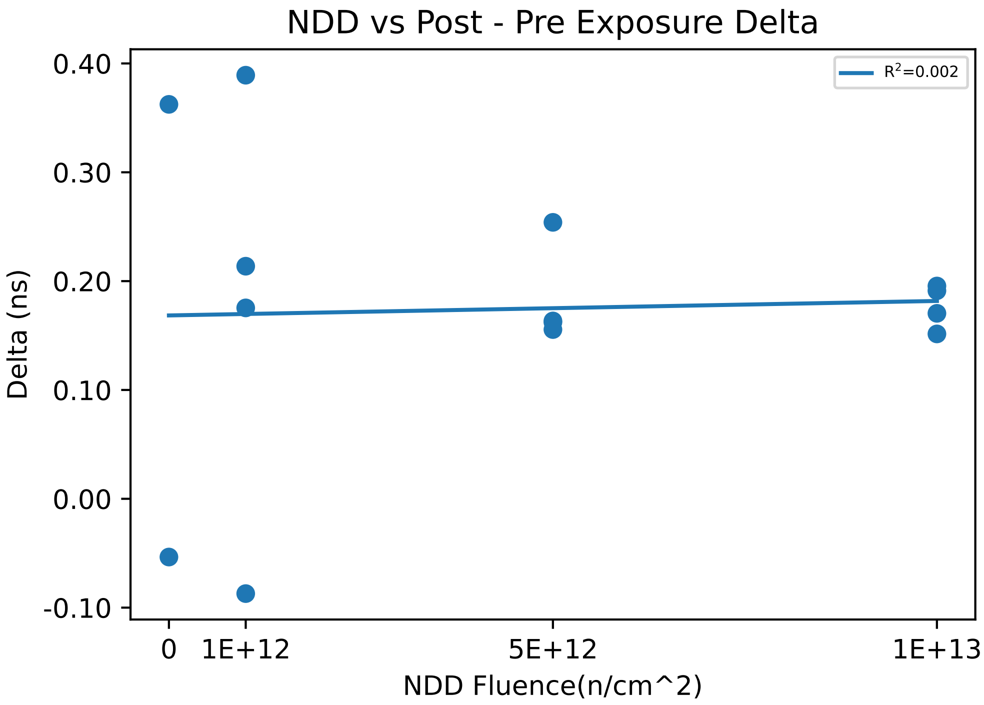
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	24.172	24.142	-0.0299
2	0	Correlation	24.134	24.112	-0.0216
30	1e+12	NDD unbiased	24.135	23.882	-0.2529
31	1e+12	NDD unbiased	23.962	23.958	-0.0038
32	1e+12	NDD unbiased	24.353	24.233	-0.1204
33	1e+12	NDD unbiased	23.697	23.856	0.1587
44	5e+12	NDD unbiased	24.422	24.258	-0.1635
45	5e+12	NDD unbiased	24.4	24.159	-0.2414
46	5e+12	NDD unbiased	24.403	24.29	-0.1125
47	5e+12	NDD unbiased	24.341	24.164	-0.1771
50	1e+13	NDD unbiased	24.156	24.396	0.2401
51	1e+13	NDD unbiased	24.283	24.117	-0.1664
52	1e+13	NDD unbiased	24.079	24.224	0.145
53	1e+13	NDD unbiased	23.862	24.071	0.2093

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	24.134	24.153	24.172	0.026658	24.112	24.127	24.142	0.020789	-0.0299	-0.02575	-0.0216	0.005869
1e+12	23.697	24.037	24.353	0.27734	23.856	23.982	24.233	0.17261	-0.2529	-0.0546	0.1587	0.17486
5e+12	24.341	24.391	24.422	0.034755	24.159	24.218	24.29	0.066442	-0.2414	-0.17363	-0.1125	0.053054
1e+13	23.862	24.095	24.283	0.17683	24.071	24.202	24.396	0.14442	-0.1664	0.107	0.2401	0.18652

Device Test: 110.9 SW_T_HPHL_IIM(_Prop Delay HO Off IIM Interlock Disable VIN_10V)





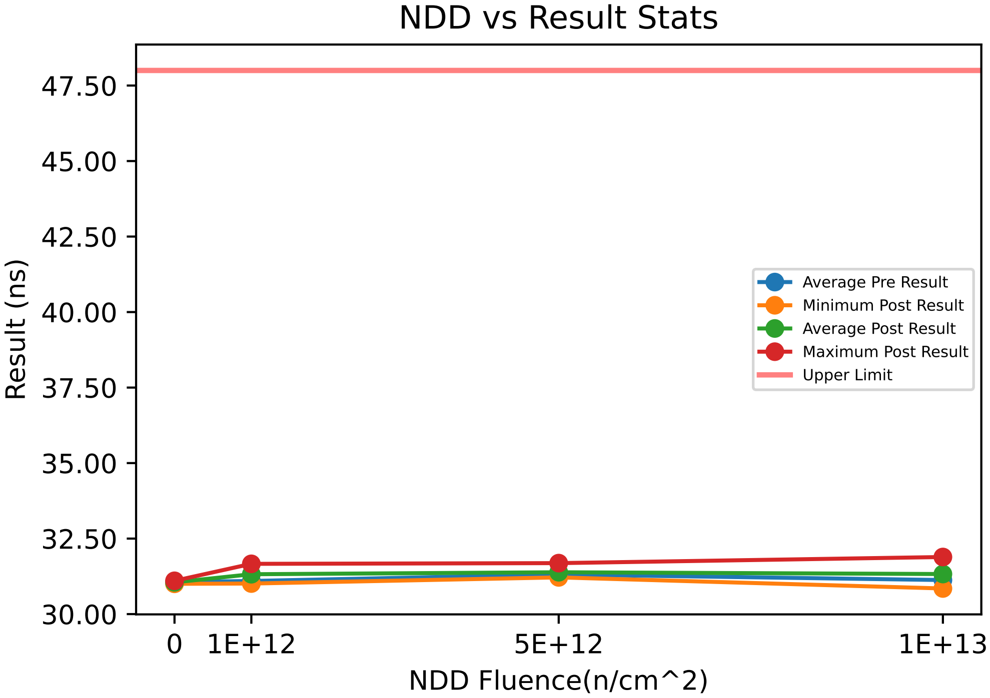
Test Results (Upper Limit = 40.0 (ns))

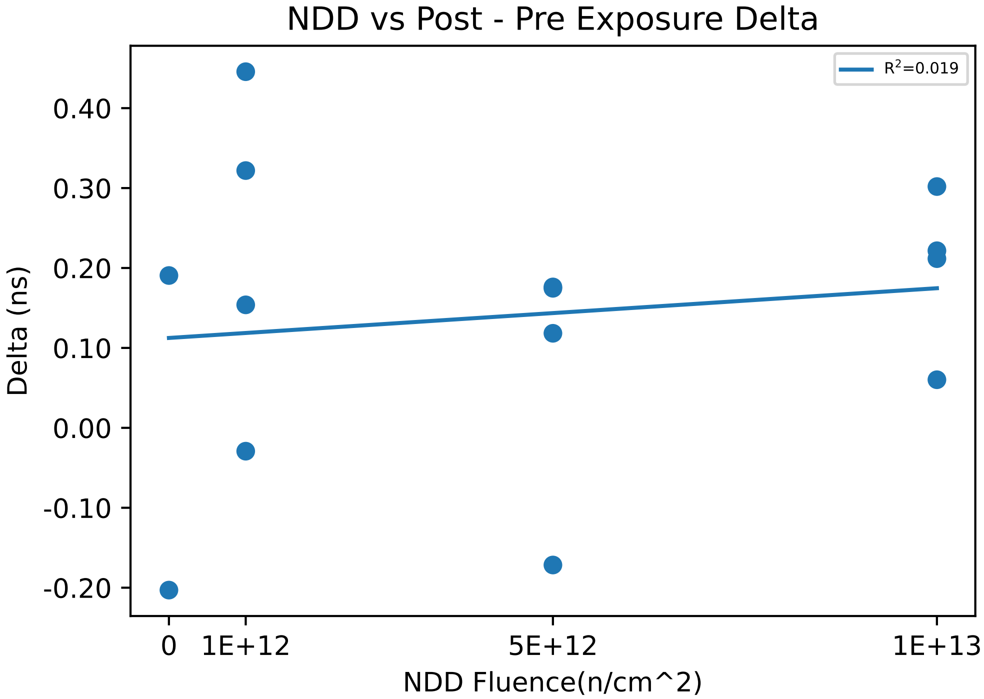
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	26.367	26.314	-0.0535
2	0	Correlation	26.452	26.814	0.3624
30	1e+12	NDD unbiased	26.312	26.701	0.3892
31	1e+12	NDD unbiased	26.522	26.435	-0.0871
32	1e+12	NDD unbiased	27.049	27.224	0.1754
33	1e+12	NDD unbiased	26.56	26.774	0.2137
44	5e+12	NDD unbiased	26.396	26.559	0.1622
45	5e+12	NDD unbiased	26.547	26.801	0.254
46	5e+12	NDD unbiased	26.7	26.855	0.1555
47	5e+12	NDD unbiased	26.616	26.78	0.1634
50	1e+13	NDD unbiased	26.948	27.1	0.1515
51	1e+13	NDD unbiased	26.421	26.592	0.1704
52	1e+13	NDD unbiased	26.685	26.88	0.1955
53	1e+13	NDD unbiased	26.312	26.504	0.1912

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	26.367	26.41	26.452	0.059538	26.314	26.564	26.814	0.35362	-0.0535	0.15445	0.3624	0.29409
1e+12	26.312	26.611	27.049	0.31174	26.435	26.784	27.224	0.32792	-0.0871	0.1728	0.3892	0.19669
5e+12	26.396	26.565	26.7	0.12849	26.559	26.749	26.855	0.13058	0.1555	0.18377	0.254	0.046946
1e+13	26.312	26.592	26.948	0.28441	26.504	26.769	27.1	0.27294	0.1515	0.17715	0.1955	0.020311

Device Test: 111.0 SW_T_LPHL_PWM(_Prop Delay LO Off PWM VIN_12V)





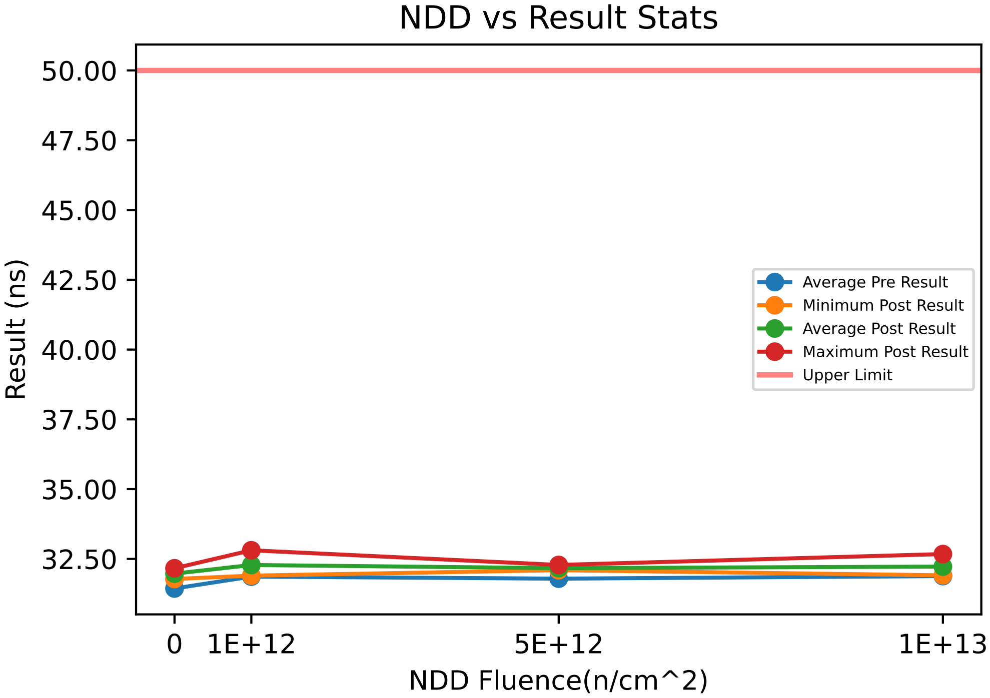
Test Results (Upper Limit = 48.0 (ns))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	30.911	31.102	0.1906
2	0	Correlation	31.206	31.003	-0.203
30	1e+12	NDD unbiased	30.824	31.27	0.4456
31	1e+12	NDD unbiased	31.041	31.011	-0.0292
32	1e+12	NDD unbiased	31.18	31.334	0.1539
33	1e+12	NDD unbiased	31.342	31.664	0.3219
44	5e+12	NDD unbiased	31.513	31.687	0.1746
45	5e+12	NDD unbiased	31.387	31.215	-0.1716
46	5e+12	NDD unbiased	31.254	31.372	0.1183
47	5e+12	NDD unbiased	31.089	31.266	0.1763
50	1e+13	NDD unbiased	31.678	31.89	0.2117
51	1e+13	NDD unbiased	30.788	30.848	0.0602
52	1e+13	NDD unbiased	31.068	31.37	0.3019
53	1e+13	NDD unbiased	30.975	31.197	0.2216

Test Statistics (ns)

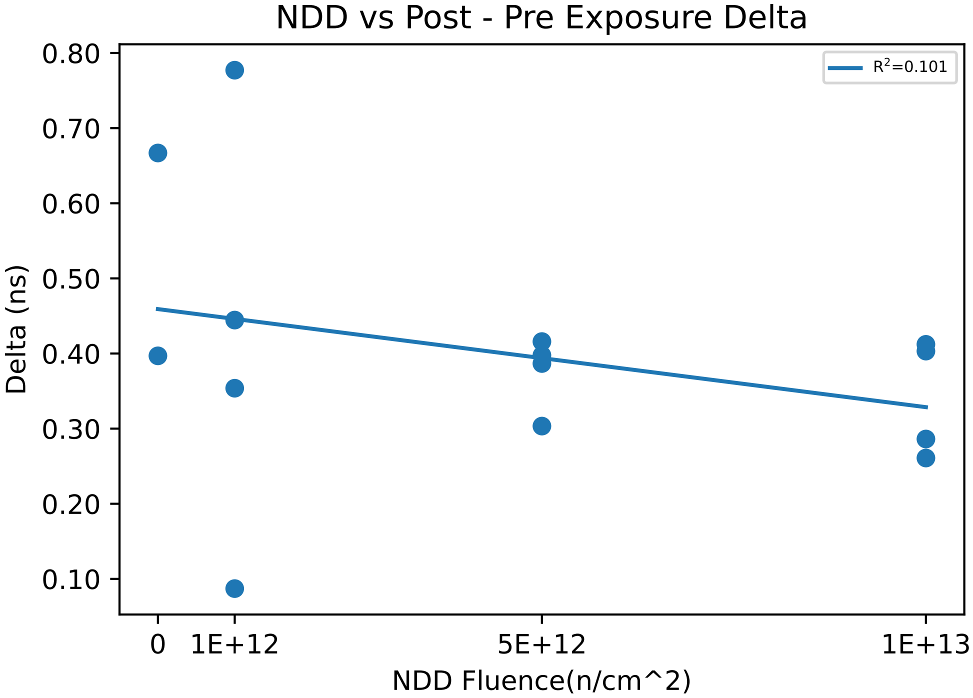
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	30.911	31.058	31.206	0.2081	31.003	31.052	31.102	0.070216	-0.203	-0.0062	0.1906	0.27832
1e+12	30.824	31.097	31.342	0.21942	31.011	31.32	31.664	0.26838	-0.0292	0.22305	0.4456	0.20633
5e+12	31.089	31.311	31.513	0.18141	31.215	31.385	31.687	0.2119	-0.1716	0.0744	0.1763	0.1662
1e+13	30.788	31.127	31.678	0.38526	30.848	31.326	31.89	0.43397	0.0602	0.19885	0.3019	0.10087

Device Test: 111.1 SW_T_HPHL_PWM(_Prop Delay HO Off PWM VIN_12V)



Test Results (Upper Limit = 50.0 (ns))

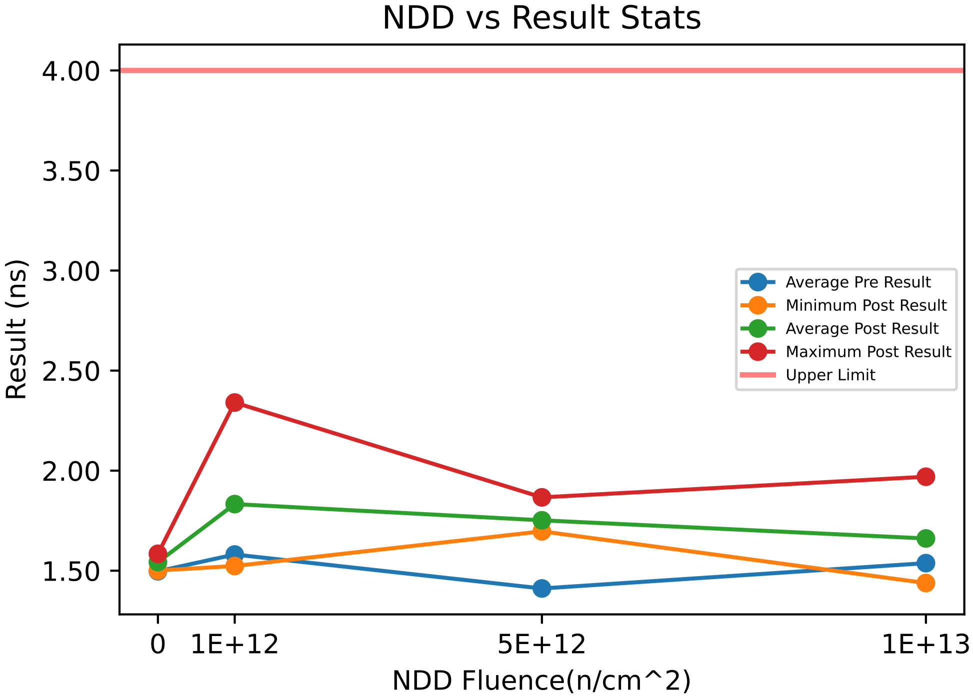
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	31.384	31.781	0.3969
2	0	Correlation	31.497	32.164	0.6669
30	1e+12	NDD unbiased	31.397	32.174	0.7771
31	1e+12	NDD unbiased	31.813	31.9	0.0871
32	1e+12	NDD unbiased	32.364	32.809	0.4445
33	1e+12	NDD unbiased	31.889	32.242	0.3538
44	5e+12	NDD unbiased	31.793	32.191	0.3976
45	5e+12	NDD unbiased	31.799	32.102	0.3034
46	5e+12	NDD unbiased	31.897	32.283	0.3867
47	5e+12	NDD unbiased	31.68	32.096	0.4159
50	1e+13	NDD unbiased	32.387	32.673	0.2862
51	1e+13	NDD unbiased	31.508	31.911	0.4032
52	1e+13	NDD unbiased	32.019	32.28	0.2609
53	1e+13	NDD unbiased	31.622	32.034	0.4122

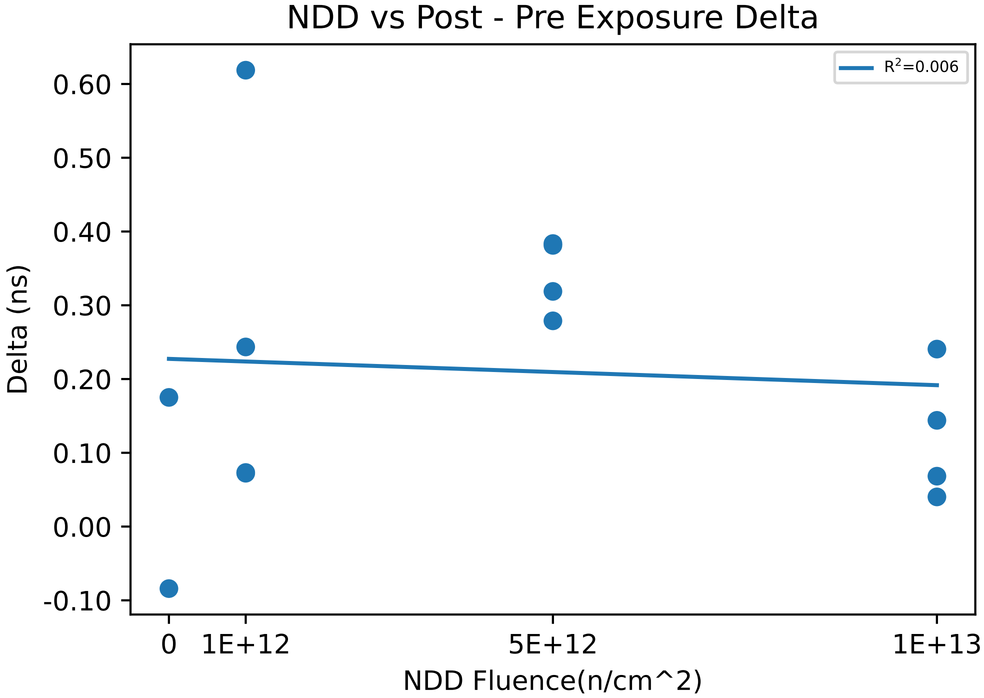


Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	31.384	31.44	31.497	0.080044	31.781	31.972	32.164	0.27096	0.3969	0.5319	0.6669	0.19092
1e+12	31.397	31.866	32.364	0.39653	31.9	32.281	32.809	0.38159	0.0871	0.41563	0.7771	0.28475
5e+12	31.68	31.792	31.897	0.08866	32.096	32.168	32.283	0.088188	0.3034	0.3759	0.4159	0.049812
1e+13	31.508	31.884	32.387	0.40057	31.911	32.225	32.673	0.33606	0.2609	0.34063	0.4122	0.078224

Device Test: 111.11 SW_T_MATCH_OFF(_Delay Match LO Off HO On IIM Interlock VIN_12V)





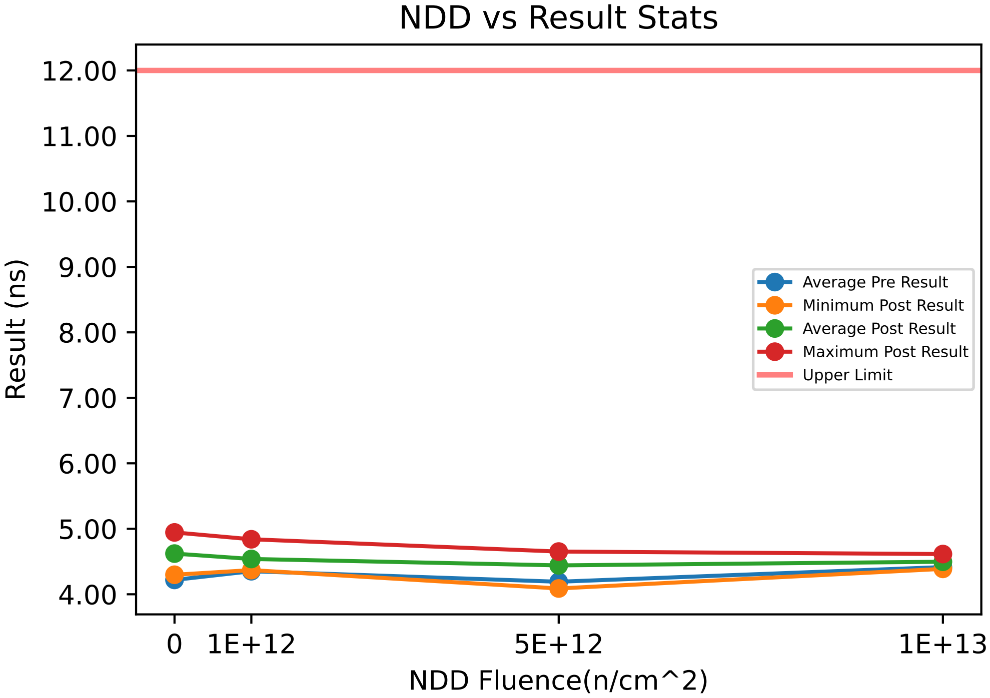
Test Results (Upper Limit = 4.0 (ns))

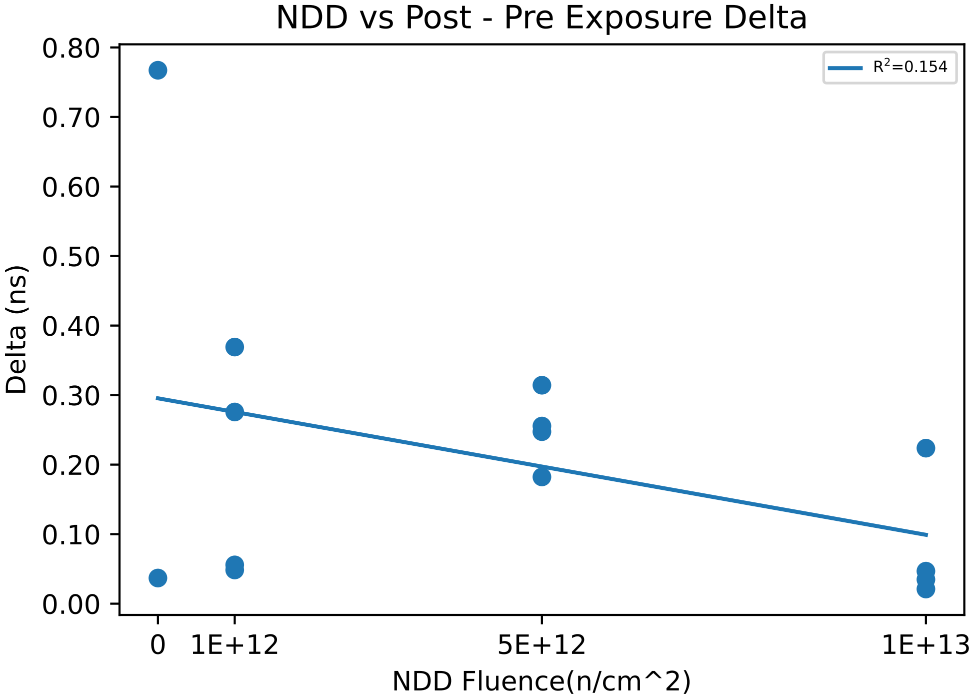
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	1.3258	1.5009	0.1751
2	0	Correlation	1.6684	1.5843	-0.0841
30	1e+12	NDD unbiased	1.2558	1.8745	0.6187
31	1e+12	NDD unbiased	1.4501	1.5234	0.0733
32	1e+12	NDD unbiased	1.3495	1.593	0.2435
33	1e+12	NDD unbiased	2.2681	2.3404	0.0723
44	5e+12	NDD unbiased	1.5477	1.8665	0.3188
45	5e+12	NDD unbiased	1.3542	1.7379	0.3837
46	5e+12	NDD unbiased	1.4177	1.6966	0.2789
47	5e+12	NDD unbiased	1.3249	1.7061	0.3812
50	1e+13	NDD unbiased	1.8255	1.9695	0.144
51	1e+13	NDD unbiased	1.1977	1.4383	0.2406
52	1e+13	NDD unbiased	1.658	1.6982	0.0402
53	1e+13	NDD unbiased	1.4699	1.5382	0.0683

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.3258	1.4971	1.6684	0.24225	1.5009	1.5426	1.5843	0.058973	-0.0841	0.0455	0.1751	0.18328
1e+12	1.2558	1.5809	2.2681	0.46497	1.5234	1.8328	2.3404	0.37087	0.0723	0.25195	0.6187	0.2574
5e+12	1.3249	1.4111	1.5477	0.098946	1.6966	1.7518	1.8665	0.078496	0.2789	0.34065	0.3837	0.050951
1e+13	1.1977	1.5378	1.8255	0.26926	1.4383	1.661	1.9695	0.23183	0.0402	0.12328	0.2406	0.089663

Device Test: 111.12 SW_T_MATCH_ON(_Delay Match LO On HO Off IIM Interlock Disable VIN_12V)


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

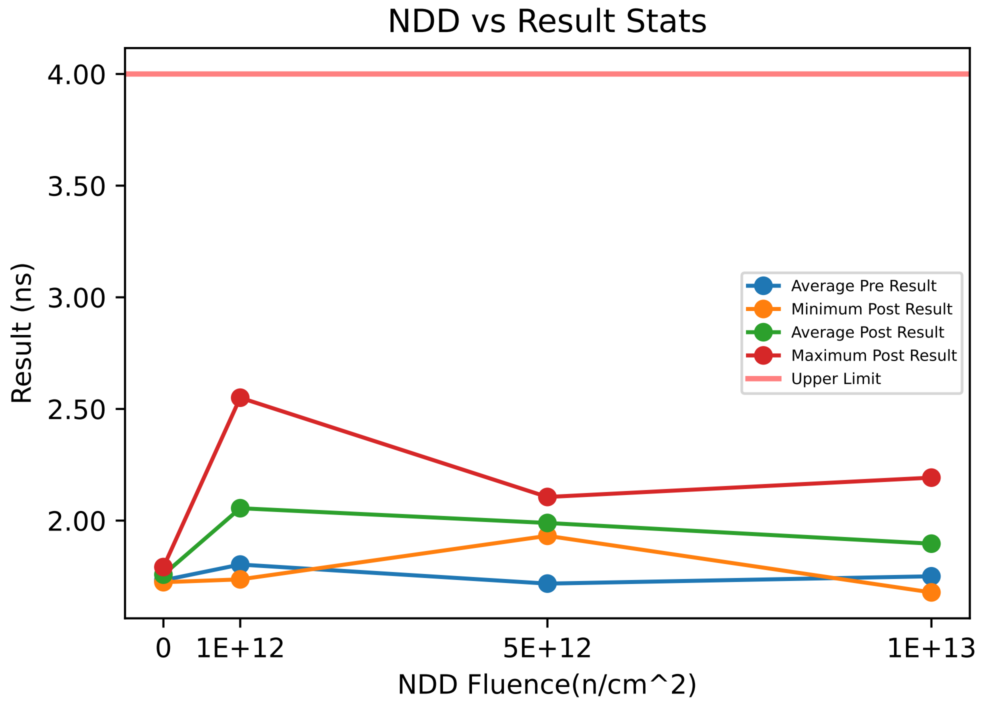
Test Results (Upper Limit = 12.0 (ns))

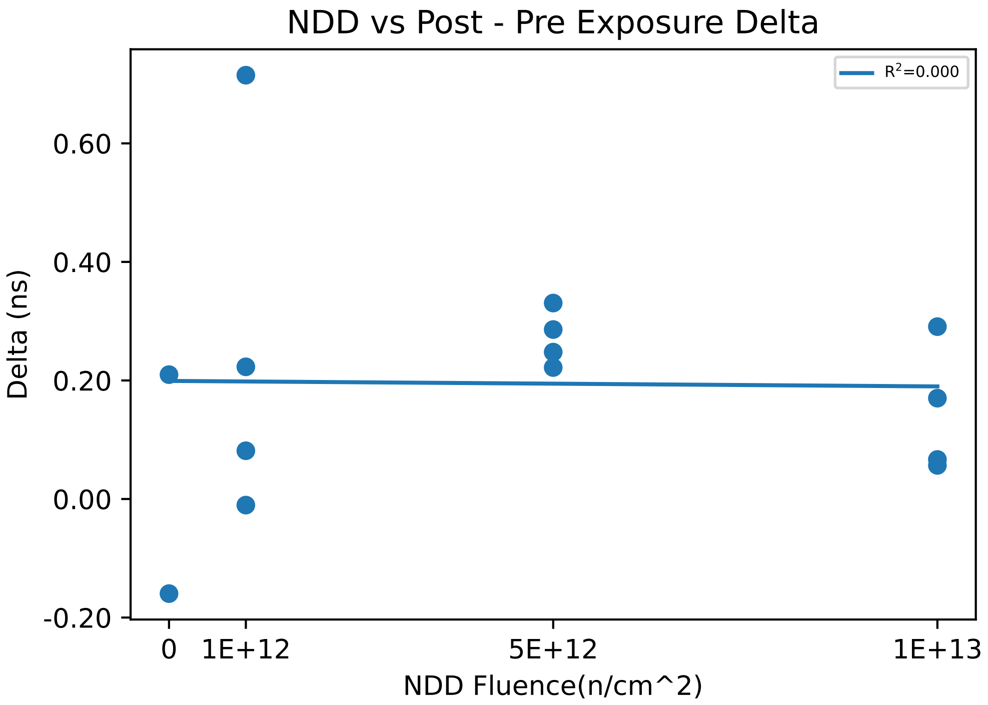
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	4.2609	4.2978	0.0369
2	0	Correlation	4.1774	4.9446	0.7672
30	1e+12	NDD unbiased	4.2078	4.5769	0.3691
31	1e+12	NDD unbiased	4.3222	4.3707	0.0485
32	1e+12	NDD unbiased	4.5642	4.8399	0.2757
33	1e+12	NDD unbiased	4.3131	4.3689	0.0558
44	5e+12	NDD unbiased	3.8329	4.0884	0.2555
45	5e+12	NDD unbiased	4.3284	4.5107	0.1823
46	5e+12	NDD unbiased	4.4049	4.6523	0.2474
47	5e+12	NDD unbiased	4.1989	4.5131	0.3142
50	1e+13	NDD unbiased	4.5674	4.6142	0.0468
51	1e+13	NDD unbiased	4.2587	4.4824	0.2237
52	1e+13	NDD unbiased	4.4812	4.5023	0.0211
53	1e+13	NDD unbiased	4.3531	4.3879	0.0348

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.1774	4.2191	4.2609	0.059043	4.2978	4.6212	4.9446	0.45736	0.0369	0.40205	0.7672	0.5164
1e+12	4.2078	4.3518	4.5642	0.1508	4.3689	4.5391	4.8399	0.22304	0.0485	0.18728	0.3691	0.16065
5e+12	3.8329	4.1913	4.4049	0.25359	4.0884	4.4411	4.6523	0.24429	0.1823	0.24985	0.3142	0.053981
1e+13	4.2587	4.4151	4.5674	0.13647	4.3879	4.4967	4.6142	0.092879	0.0211	0.0816	0.2237	0.095313

Device Test: 111.13 SW_T_MATCH_OFF(_Delay Match LO Off HO On IIM Interlock Disable VIN_12V)





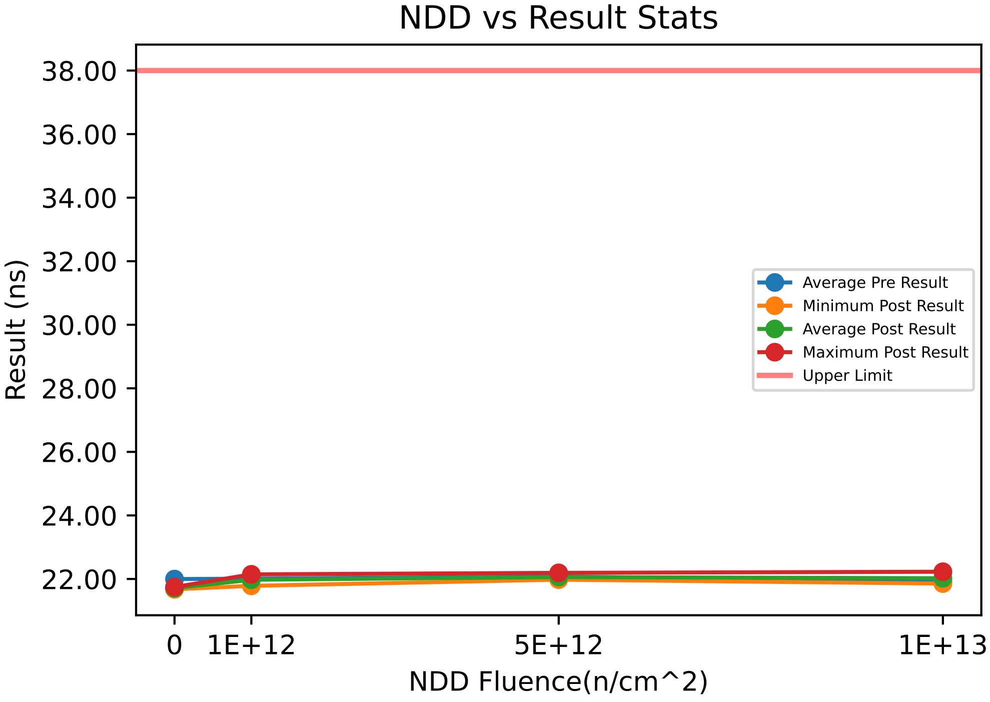
Test Results (Upper Limit = 4.0 (ns))

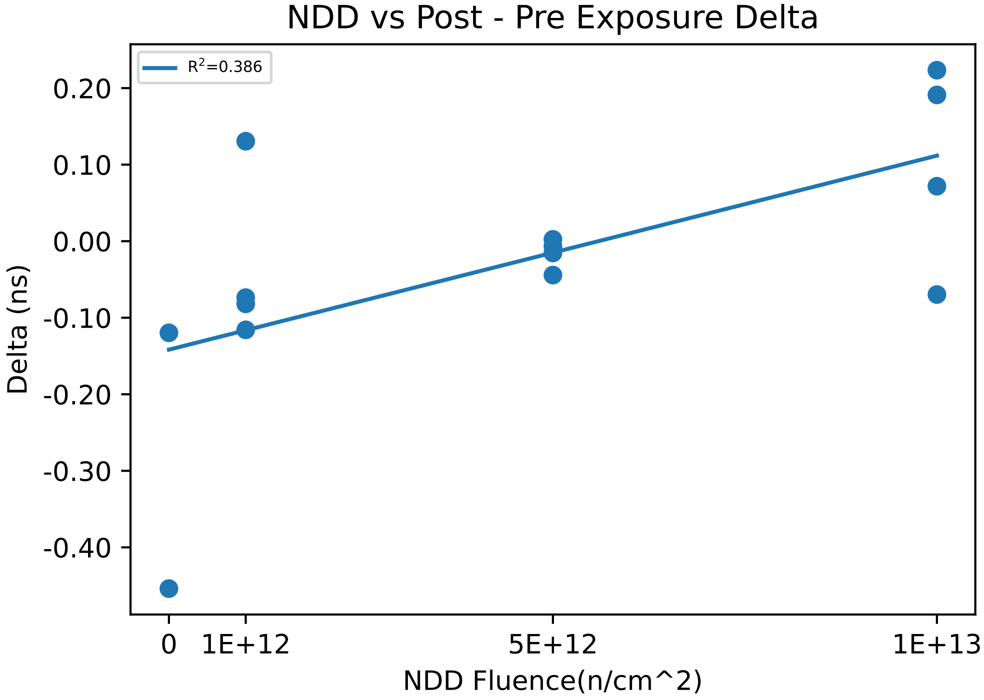
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	1.5144	1.7242	0.2098
2	0	Correlation	1.9515	1.7919	-0.1596
30	1e+12	NDD unbiased	1.3785	2.0935	0.715
31	1e+12	NDD unbiased	1.7471	1.7368	-0.0103
32	1e+12	NDD unbiased	1.6183	1.8413	0.223
33	1e+12	NDD unbiased	2.469	2.5504	0.0814
44	5e+12	NDD unbiased	1.8199	2.1058	0.2859
45	5e+12	NDD unbiased	1.7123	1.9341	0.2218
46	5e+12	NDD unbiased	1.6841	1.9319	0.2478
47	5e+12	NDD unbiased	1.6553	1.9859	0.3306
50	1e+13	NDD unbiased	2.1357	2.1924	0.0567
51	1e+13	NDD unbiased	1.3877	1.6785	0.2908
52	1e+13	NDD unbiased	1.7833	1.9534	0.1701
53	1e+13	NDD unbiased	1.6958	1.7625	0.0667

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.5144	1.7329	1.9515	0.30908	1.7242	1.758	1.7919	0.047871	-0.1596	0.0251	0.2098	0.26121
1e+12	1.3785	1.8032	2.469	0.46939	1.7368	2.0555	2.5504	0.36232	-0.0103	0.25227	0.715	0.32307
5e+12	1.6553	1.7179	1.8199	0.071872	1.9319	1.9894	2.1058	0.081498	0.2218	0.27152	0.3306	0.047371
1e+13	1.3877	1.7506	2.1357	0.30772	1.6785	1.8967	2.1924	0.22824	0.0567	0.14608	0.2908	0.10926

Device Test: 111.2 SW_T_LPLH_IIM(_Prop Delay LO On IIM Interlock VIN_12V)





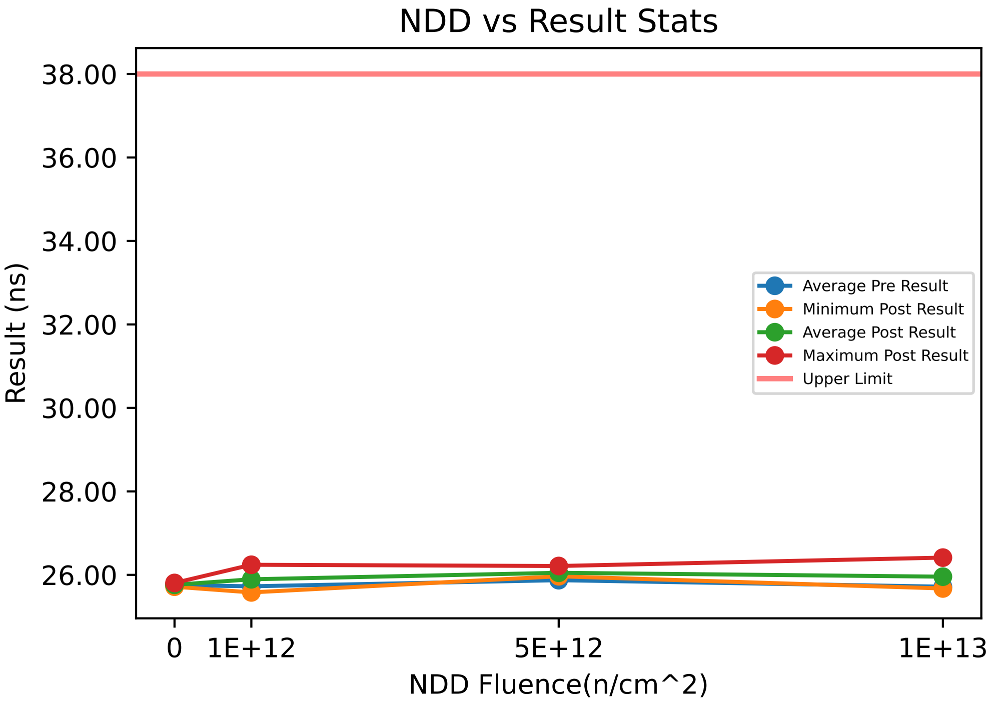
Test Results (Upper Limit = 38.0 (ns))

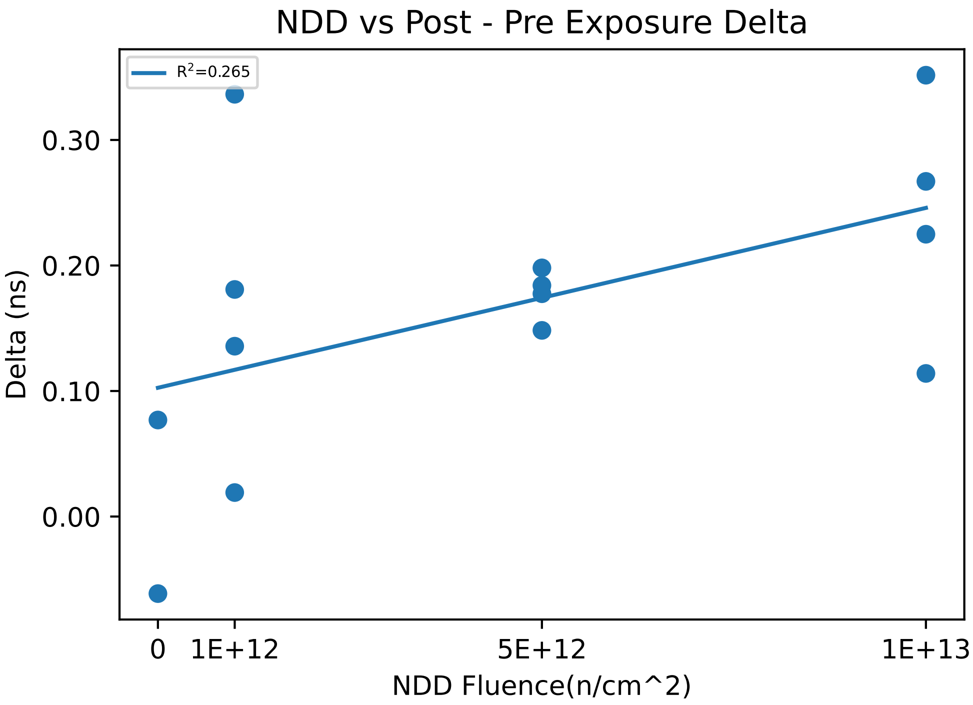
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	21.866	21.746	-0.1197
2	0	Correlation	22.128	21.675	-0.4539
30	1e+12	NDD unbiased	21.919	21.837	-0.0819
31	1e+12	NDD unbiased	21.858	21.784	-0.0737
32	1e+12	NDD unbiased	22.261	22.145	-0.1158
33	1e+12	NDD unbiased	22.003	22.134	0.1306
44	5e+12	NDD unbiased	22.199	22.192	-0.0069
45	5e+12	NDD unbiased	22.03	22.033	0.0024
46	5e+12	NDD unbiased	22.023	21.979	-0.0443
47	5e+12	NDD unbiased	22.053	22.037	-0.0154
50	1e+13	NDD unbiased	22.005	22.228	0.2234
51	1e+13	NDD unbiased	21.94	21.87	-0.0697
52	1e+13	NDD unbiased	21.945	22.136	0.1911
53	1e+13	NDD unbiased	21.784	21.855	0.0718

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	21.866	21.997	22.128	0.18583	21.675	21.71	21.746	0.050487	-0.4539	-0.2868	-0.1197	0.23632
1e+12	21.858	22.01	22.261	0.17758	21.784	21.975	22.145	0.1913	-0.1158	-0.0352	0.1306	0.11203
5e+12	22.023	22.076	22.199	0.082674	21.979	22.06	22.192	0.091737	-0.0443	-0.01605	0.0024	0.020188
1e+13	21.784	21.918	22.005	0.094466	21.855	22.023	22.228	0.1882	-0.0697	0.10415	0.2234	0.13298

Device Test: 111.3 SW_T_LPHL_IIM(_Prop Delay LO Off IIM Interlock VIN_12V)





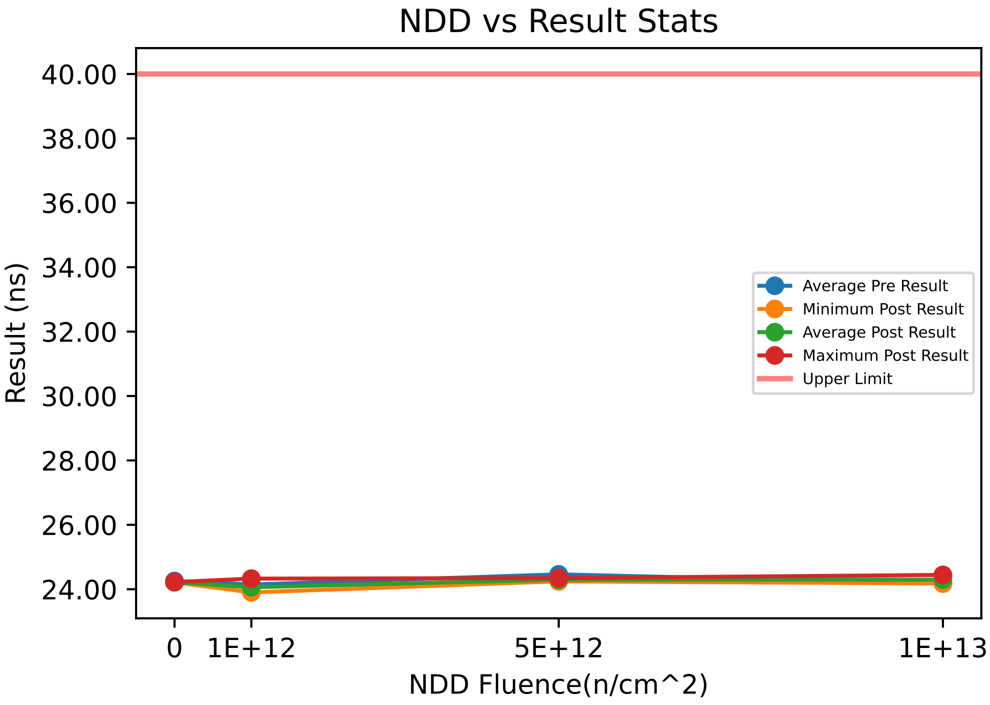
Test Results (Upper Limit = 38.0 (ns))

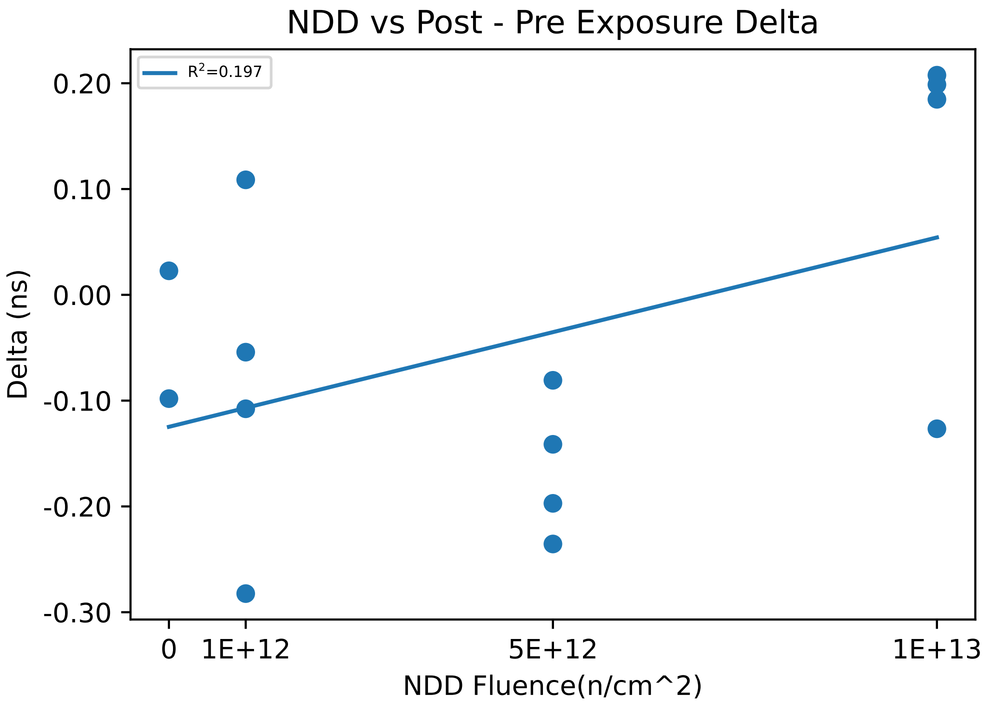
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	25.639	25.716	0.0769
2	0	Correlation	25.868	25.806	-0.0614
30	1e+12	NDD unbiased	25.496	25.833	0.3364
31	1e+12	NDD unbiased	25.561	25.58	0.0191
32	1e+12	NDD unbiased	25.786	25.922	0.1357
33	1e+12	NDD unbiased	26.061	26.242	0.1809
44	5e+12	NDD unbiased	26.035	26.212	0.1775
45	5e+12	NDD unbiased	25.835	25.983	0.1483
46	5e+12	NDD unbiased	25.839	26.037	0.1981
47	5e+12	NDD unbiased	25.782	25.966	0.1841
50	1e+13	NDD unbiased	26.062	26.413	0.3516
51	1e+13	NDD unbiased	25.56	25.674	0.114
52	1e+13	NDD unbiased	25.799	26.023	0.2249
53	1e+13	NDD unbiased	25.45	25.717	0.267

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	25.639	25.753	25.868	0.1615	25.716	25.761	25.806	0.06371	-0.0614	0.00775	0.0769	0.097793
1e+12	25.496	25.726	26.061	0.25549	25.58	25.894	26.242	0.27331	0.0191	0.16803	0.3364	0.13133
5e+12	25.782	25.873	26.035	0.11132	25.966	26.05	26.212	0.1127	0.1483	0.177	0.1981	0.020973
1e+13	25.45	25.718	26.062	0.27172	25.674	25.957	26.413	0.34176	0.114	0.23937	0.3516	0.098803

Device Test: 111.4 SW_T_HPLH_IIM(_Prop Delay HO On IIM Interlock VIN_12V)


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

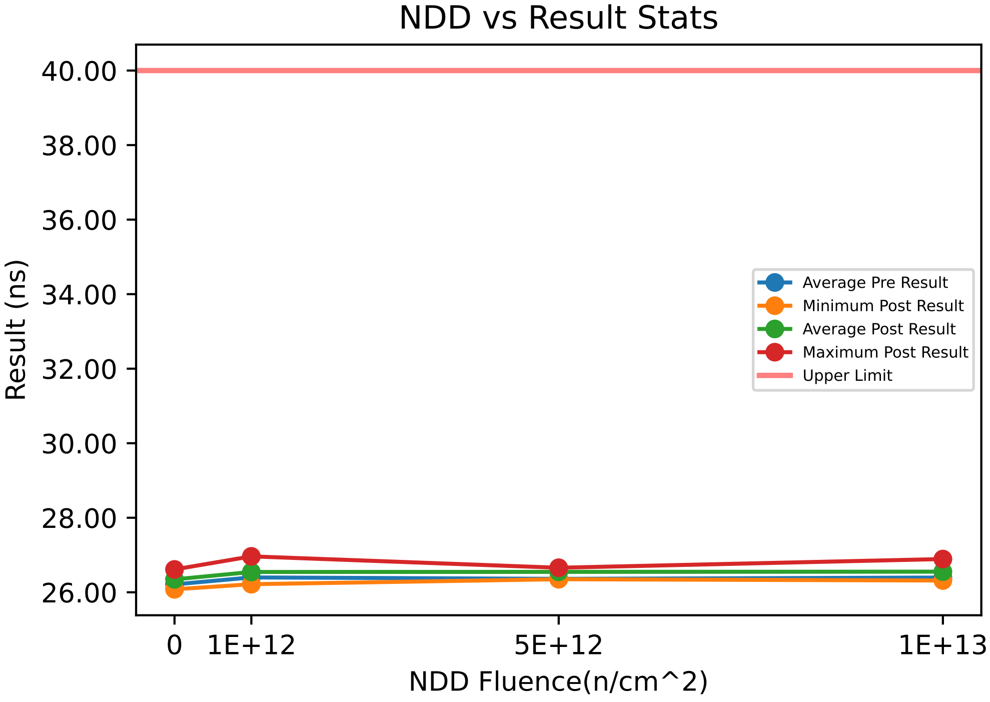
Test Results (Upper Limit = 40.0 (ns))

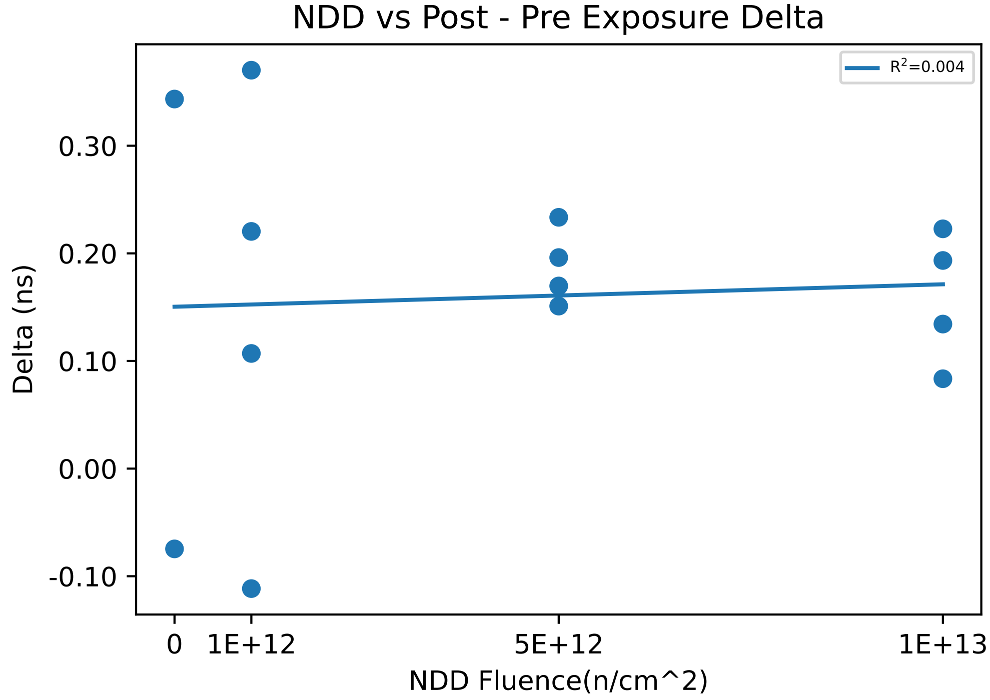
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	24.313	24.215	-0.0981
2	0	Correlation	24.199	24.222	0.0227
30	1e+12	NDD unbiased	24.241	23.958	-0.2824
31	1e+12	NDD unbiased	24.111	24.057	-0.0542
32	1e+12	NDD unbiased	24.437	24.329	-0.1077
33	1e+12	NDD unbiased	23.793	23.902	0.1087
44	5e+12	NDD unbiased	24.487	24.346	-0.1413
45	5e+12	NDD unbiased	24.481	24.245	-0.2355
46	5e+12	NDD unbiased	24.421	24.34	-0.0808
47	5e+12	NDD unbiased	24.457	24.26	-0.1971
50	1e+13	NDD unbiased	24.236	24.444	0.2076
51	1e+13	NDD unbiased	24.362	24.236	-0.1266
52	1e+13	NDD unbiased	24.14	24.325	0.1848
53	1e+13	NDD unbiased	23.98	24.179	0.1987

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	24.199	24.256	24.313	0.080681	24.215	24.219	24.222	0.0047376	-0.0981	-0.0377	0.0227	0.085418
1e+12	23.793	24.145	24.437	0.27037	23.902	24.061	24.329	0.18953	-0.2824	-0.0839	0.1087	0.16119
5e+12	24.421	24.462	24.487	0.030037	24.245	24.298	24.346	0.052616	-0.2355	-0.16368	-0.0808	0.067441
1e+13	23.98	24.18	24.362	0.16124	24.179	24.296	24.444	0.11564	-0.1266	0.11612	0.2076	0.16209

Device Test: 111.5 SW_T_HPHL_IIM(_Prop Delay HO Off IIM Interlock VIN_12V)





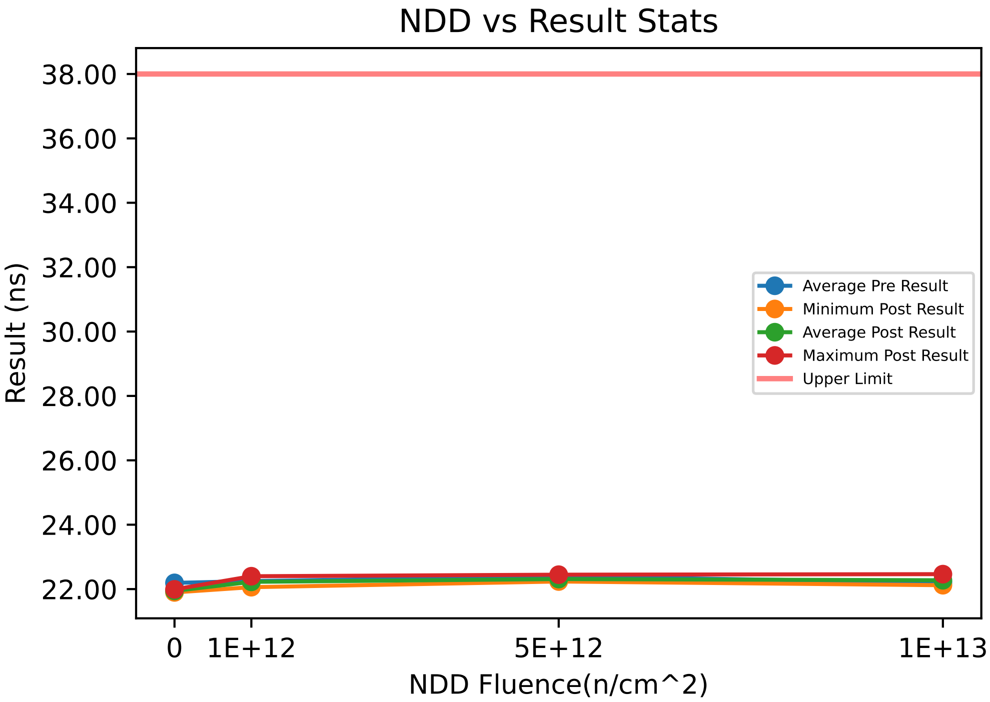
Test Results (Upper Limit = 40.0 (ns))

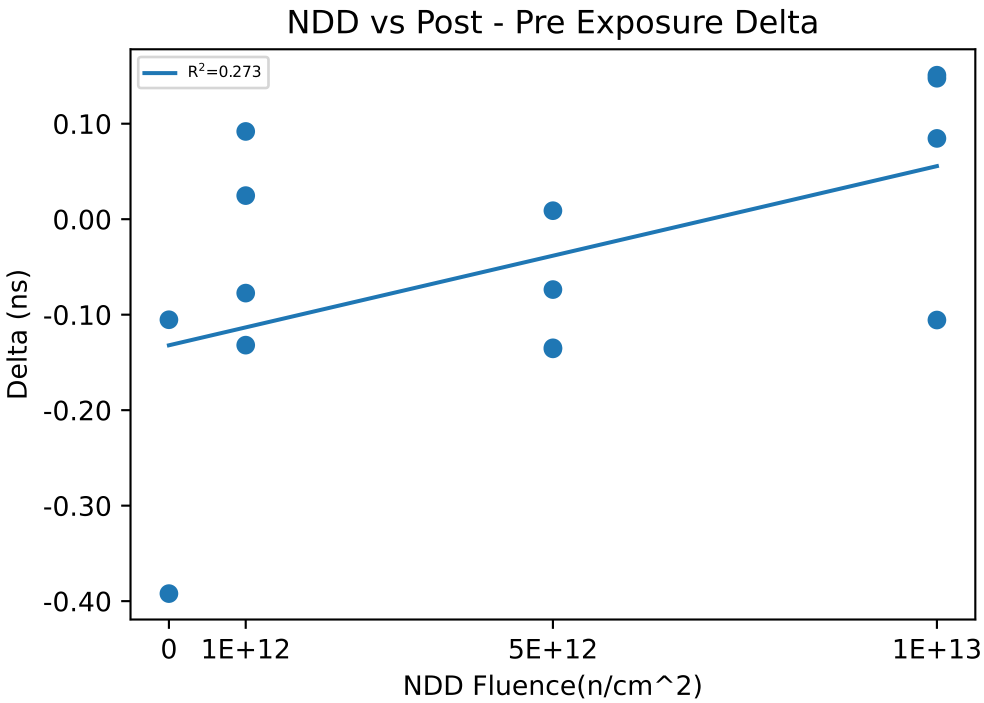
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	26.154	26.08	-0.0746
2	0	Correlation	26.27	26.613	0.3434
30	1e+12	NDD unbiased	26.091	26.462	0.3702
31	1e+12	NDD unbiased	26.329	26.217	-0.1115
32	1e+12	NDD unbiased	26.857	26.964	0.107
33	1e+12	NDD unbiased	26.318	26.538	0.2204
44	5e+12	NDD unbiased	26.117	26.351	0.2335
45	5e+12	NDD unbiased	26.431	26.582	0.151
46	5e+12	NDD unbiased	26.462	26.658	0.1961
47	5e+12	NDD unbiased	26.431	26.601	0.1697
50	1e+13	NDD unbiased	26.698	26.892	0.1934
51	1e+13	NDD unbiased	26.274	26.358	0.0835
52	1e+13	NDD unbiased	26.515	26.65	0.1343
53	1e+13	NDD unbiased	26.093	26.316	0.2228

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	26.154	26.212	26.27	0.081812	26.08	26.347	26.613	0.37738	-0.0746	0.1344	0.3434	0.29557
1e+12	26.091	26.399	26.857	0.32452	26.217	26.545	26.964	0.31096	-0.1115	0.14652	0.3702	0.203
5e+12	26.117	26.36	26.462	0.16294	26.351	26.548	26.658	0.13559	0.151	0.18757	0.2335	0.035773
1e+13	26.093	26.395	26.698	0.26599	26.316	26.554	26.892	0.26986	0.0835	0.1585	0.2228	0.062084

Device Test: 111.6 SW_T_LPLH_IIM(_Prop Delay LO On IIM Interlock Disable VIN_12V)


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

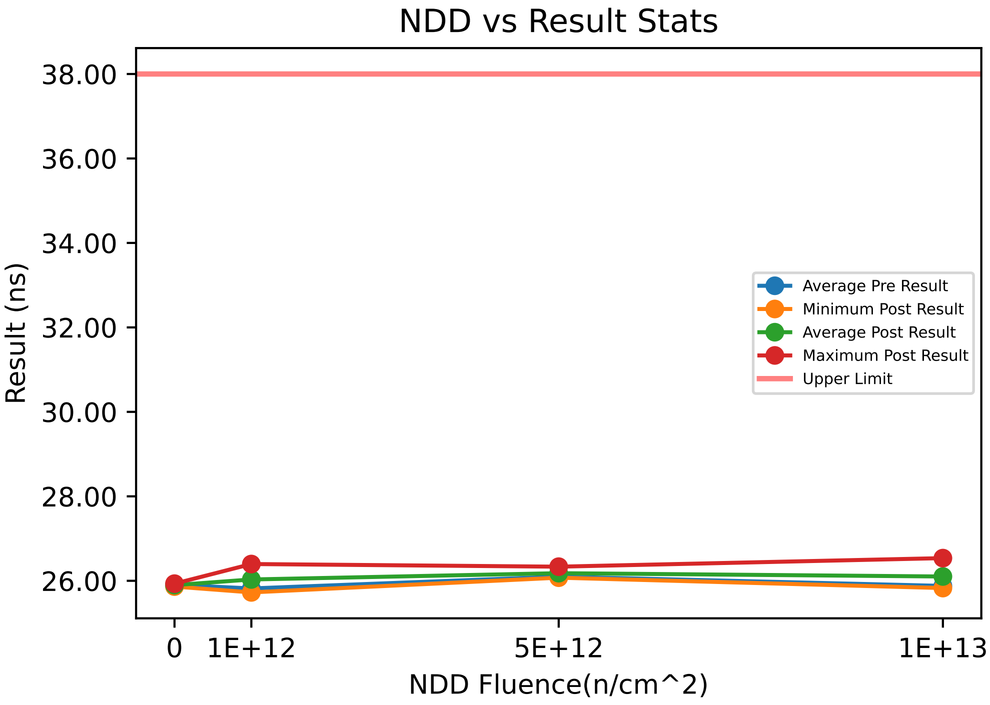
Test Results (Upper Limit = 38.0 (ns))

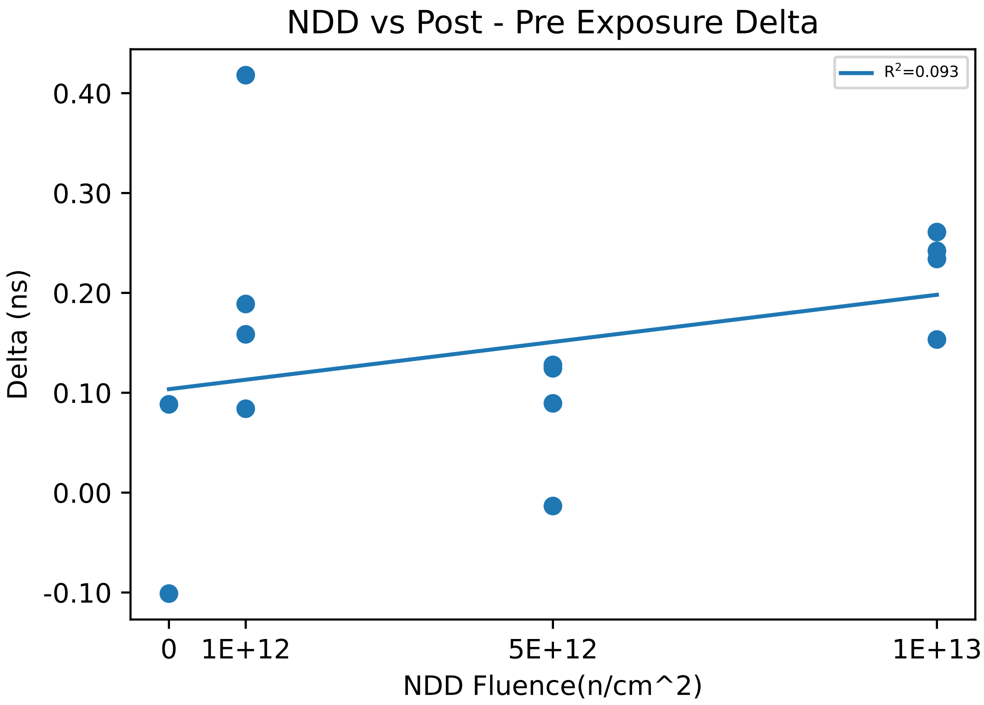
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	22.096	21.991	-0.1053
2	0	Correlation	22.289	21.897	-0.3921
30	1e+12	NDD unbiased	22.06	22.084	0.0247
31	1e+12	NDD unbiased	22.191	22.059	-0.1319
32	1e+12	NDD unbiased	22.477	22.399	-0.0774
33	1e+12	NDD unbiased	22.264	22.356	0.0919
44	5e+12	NDD unbiased	22.582	22.447	-0.1347
45	5e+12	NDD unbiased	22.267	22.276	0.0089
46	5e+12	NDD unbiased	22.309	22.236	-0.0737
47	5e+12	NDD unbiased	22.423	22.287	-0.1358
50	1e+13	NDD unbiased	22.379	22.464	0.0846
51	1e+13	NDD unbiased	22.226	22.121	-0.1056
52	1e+13	NDD unbiased	22.233	22.384	0.1508
53	1e+13	NDD unbiased	21.98	22.128	0.1476

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	22.096	22.193	22.289	0.13647	21.897	21.944	21.991	0.066327	-0.3921	-0.2487	-0.1053	0.2028
1e+12	22.06	22.248	22.477	0.1744	22.059	22.225	22.399	0.17777	-0.1319	-0.023175	0.0919	0.10049
5e+12	22.267	22.395	22.582	0.14075	22.236	22.312	22.447	0.093225	-0.1358	-0.083825	0.0089	0.068289
1e+13	21.98	22.205	22.379	0.16554	22.121	22.274	22.464	0.17618	-0.1056	0.06935	0.1508	0.12055

Device Test: 111.7 SW_T_LPHL_IIM(_Prop Delay LO Off IIM Interlock Disable VIN_12V)


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

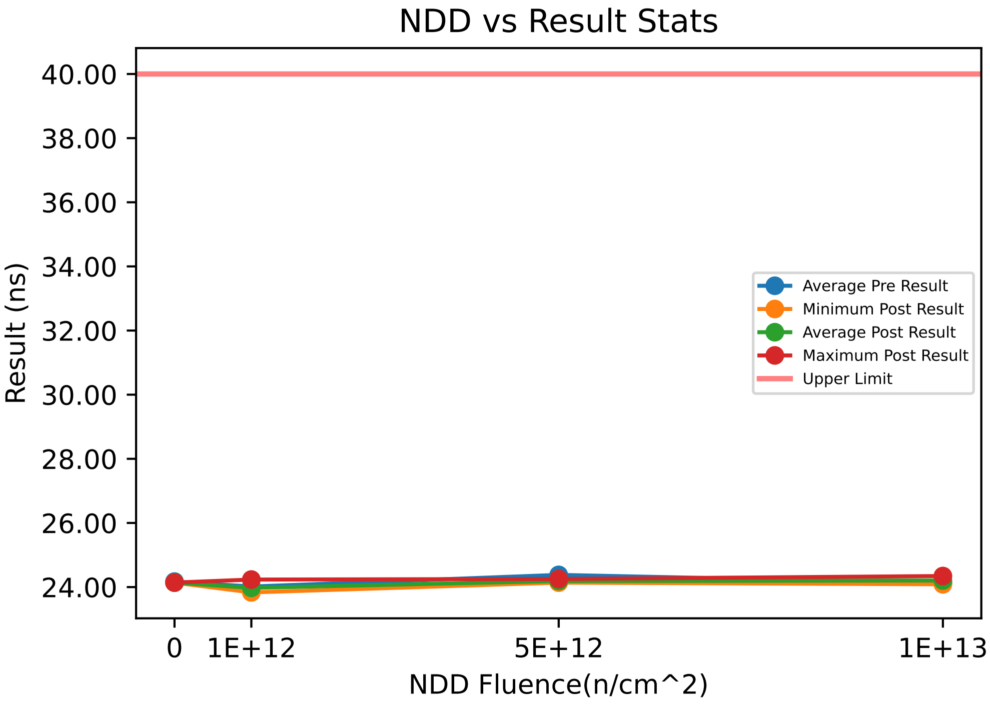
Test Results (Upper Limit = 38.0 (ns))

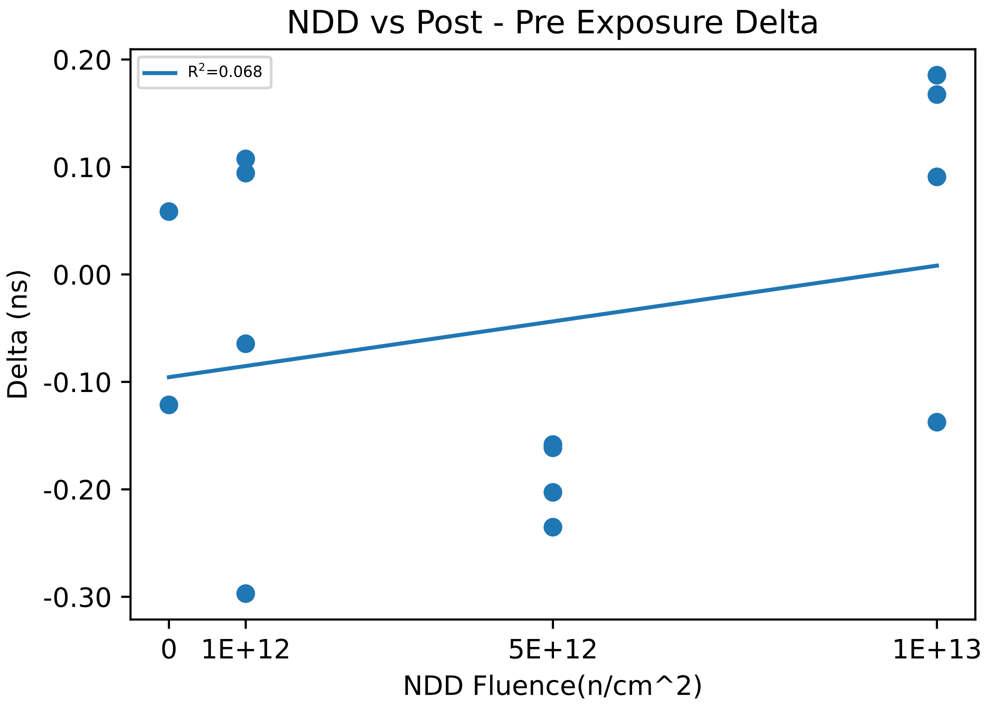
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	25.775	25.863	0.0884
2	0	Correlation	26.034	25.933	-0.1011
30	1e+12	NDD unbiased	25.51	25.928	0.418
31	1e+12	NDD unbiased	25.642	25.726	0.084
32	1e+12	NDD unbiased	25.918	26.076	0.1585
33	1e+12	NDD unbiased	26.208	26.397	0.1889
44	5e+12	NDD unbiased	26.21	26.334	0.1245
45	5e+12	NDD unbiased	26.087	26.074	-0.0134
46	5e+12	NDD unbiased	26.095	26.184	0.0894
47	5e+12	NDD unbiased	26.001	26.129	0.1279
50	1e+13	NDD unbiased	26.295	26.537	0.2421
51	1e+13	NDD unbiased	25.675	25.828	0.1533
52	1e+13	NDD unbiased	25.932	26.192	0.2609
53	1e+13	NDD unbiased	25.616	25.85	0.234

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	25.775	25.904	26.034	0.18293	25.863	25.898	25.933	0.048932	-0.1011	-0.00635	0.0884	0.134
1e+12	25.51	25.819	26.208	0.30995	25.726	26.032	26.397	0.28285	0.084	0.21235	0.418	0.14401
5e+12	26.001	26.098	26.21	0.085899	26.074	26.18	26.334	0.11227	-0.0134	0.0821	0.1279	0.066002
1e+13	25.616	25.879	26.295	0.309	25.828	26.102	26.537	0.33455	0.1533	0.22257	0.2609	0.047538

Device Test: 111.8 SW_T_HPLH_IIM(_Prop Delay HO On IIM Interlock Disable VIN_12V)





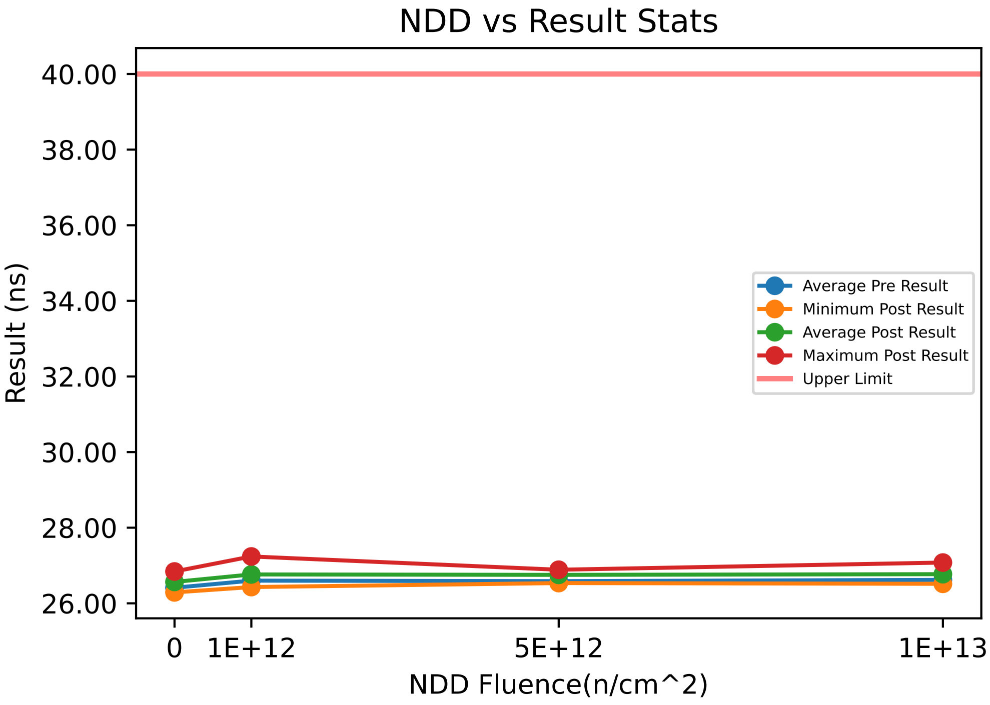
Test Results (Upper Limit = 40.0 (ns))

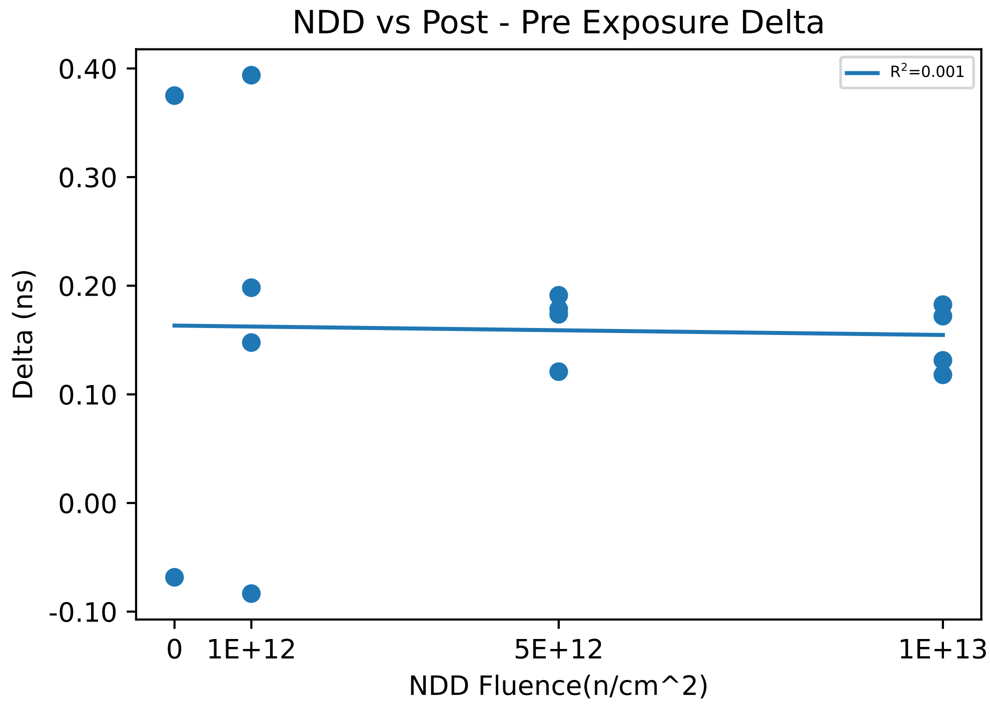
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	24.261	24.139	-0.1214
2	0	Correlation	24.082	24.141	0.0585
30	1e+12	NDD unbiased	24.131	23.834	-0.297
31	1e+12	NDD unbiased	23.894	23.989	0.0943
32	1e+12	NDD unbiased	24.299	24.235	-0.0645
33	1e+12	NDD unbiased	23.739	23.847	0.1075
44	5e+12	NDD unbiased	24.39	24.229	-0.1613
45	5e+12	NDD unbiased	24.375	24.14	-0.2352
46	5e+12	NDD unbiased	24.411	24.253	-0.1583
47	5e+12	NDD unbiased	24.346	24.143	-0.2028
50	1e+13	NDD unbiased	24.159	24.345	0.1854
51	1e+13	NDD unbiased	24.287	24.15	-0.1375
52	1e+13	NDD unbiased	24.148	24.239	0.0908
53	1e+13	NDD unbiased	23.921	24.088	0.1674

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	24.082	24.171	24.261	0.12615	24.139	24.14	24.141	0.0010607	-0.1214	-0.03145	0.0585	0.12721
1e+12	23.739	24.016	24.299	0.24838	23.834	23.976	24.235	0.18613	-0.297	-0.039925	0.1075	0.18836
5e+12	24.346	24.38	24.411	0.027523	24.14	24.191	24.253	0.058275	-0.2352	-0.1894	-0.1583	0.03667
1e+13	23.921	24.129	24.287	0.15256	24.088	24.205	24.345	0.11171	-0.1375	0.076525	0.1854	0.14846

Device Test: 111.9 SW_T_HPHL_IIM(_Prop Delay HO Off IIM Interlock Disable VIN_12V)


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

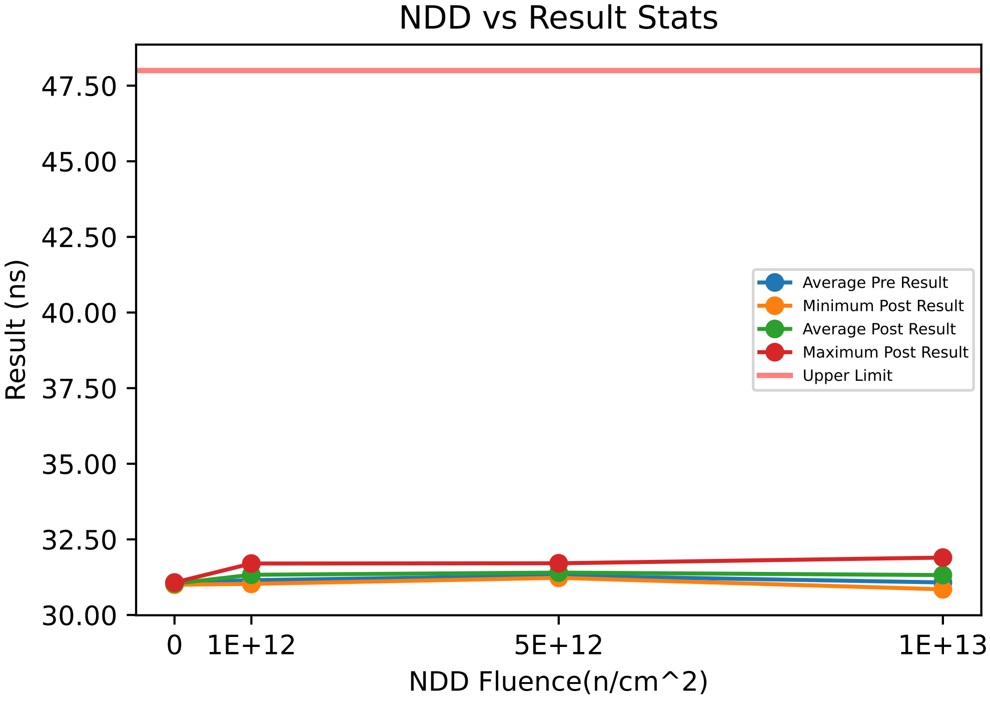
Test Results (Upper Limit = 40.0 (ns))

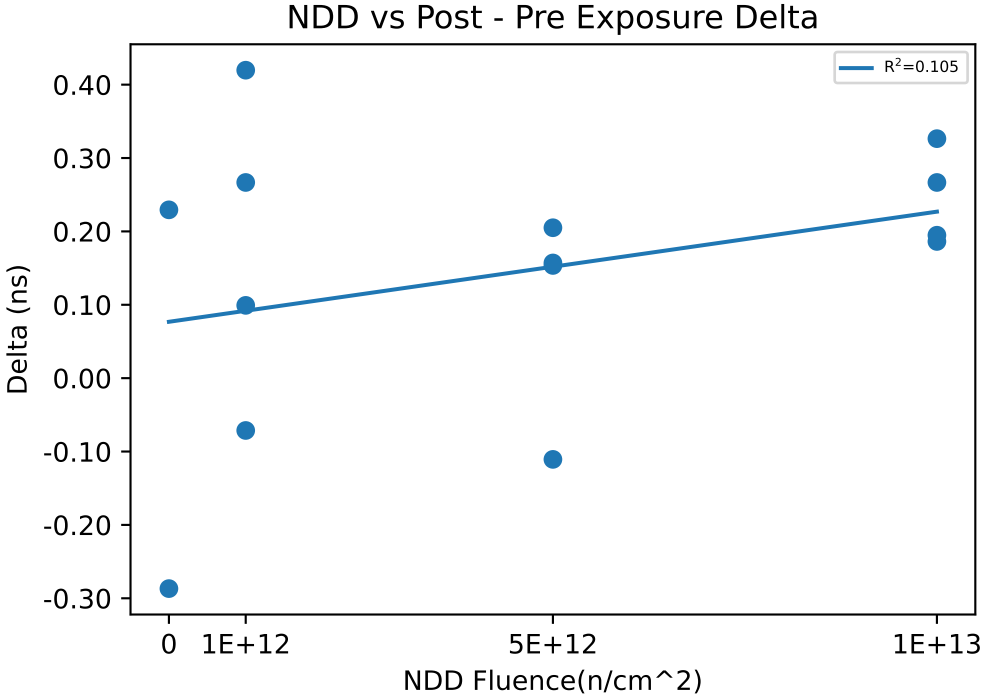
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	26.357	26.289	-0.0684
2	0	Correlation	26.467	26.842	0.375
30	1e+12	NDD unbiased	26.267	26.661	0.3938
31	1e+12	NDD unbiased	26.514	26.43	-0.0834
32	1e+12	NDD unbiased	27.041	27.239	0.1982
33	1e+12	NDD unbiased	26.578	26.725	0.1477
44	5e+12	NDD unbiased	26.415	26.536	0.1209
45	5e+12	NDD unbiased	26.596	26.787	0.1912
46	5e+12	NDD unbiased	26.714	26.888	0.1737
47	5e+12	NDD unbiased	26.622	26.8	0.1785
50	1e+13	NDD unbiased	26.947	27.078	0.1313
51	1e+13	NDD unbiased	26.485	26.603	0.118
52	1e+13	NDD unbiased	26.715	26.887	0.172
53	1e+13	NDD unbiased	26.333	26.516	0.1826

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	26.357	26.412	26.467	0.077499	26.289	26.565	26.842	0.39103	-0.0684	0.1533	0.375	0.31353
1e+12	26.267	26.6	27.041	0.32302	26.43	26.764	27.239	0.34125	-0.0834	0.16408	0.3938	0.19617
5e+12	26.415	26.587	26.714	0.12528	26.536	26.753	26.888	0.15138	0.1209	0.16607	0.1912	0.031008
1e+13	26.333	26.62	26.947	0.26847	26.516	26.771	27.078	0.25886	0.118	0.15097	0.1826	0.03118

Device Test: 112.0 SW_T_LPHL_PWM(_Prop Delay LO Off PWM VIN_14V)





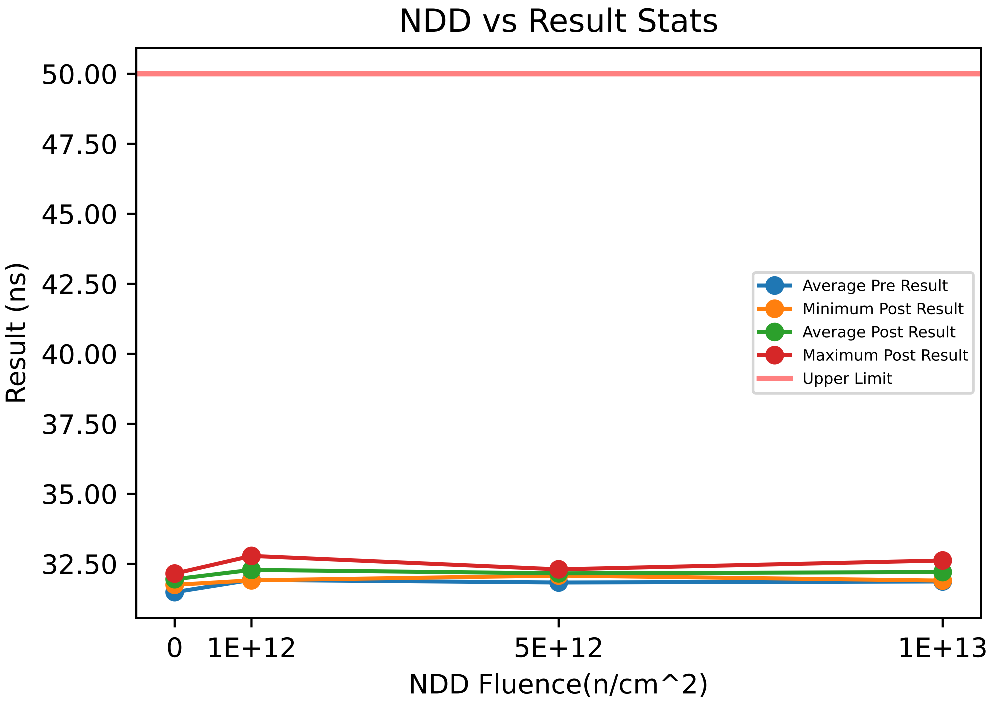
Test Results (Upper Limit = 48.0 (ns))

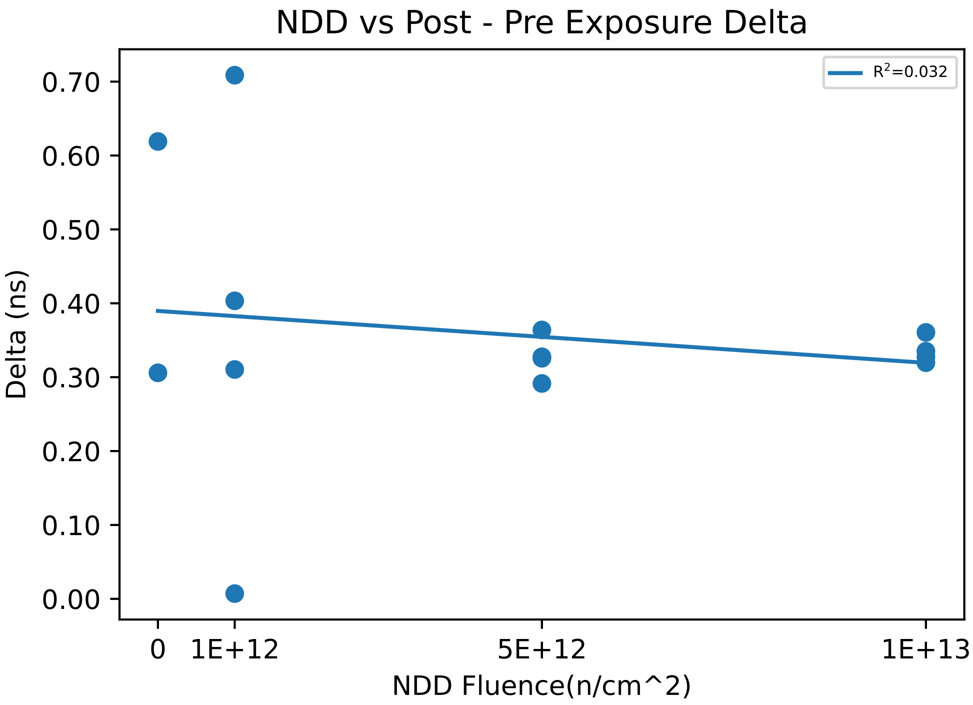
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	30.844	31.074	0.2294
2	0	Correlation	31.287	31	-0.2868
30	1e+12	NDD unbiased	30.839	31.258	0.4197
31	1e+12	NDD unbiased	31.1	31.029	-0.0713
32	1e+12	NDD unbiased	31.228	31.327	0.0992
33	1e+12	NDD unbiased	31.435	31.702	0.2667
44	5e+12	NDD unbiased	31.553	31.71	0.157
45	5e+12	NDD unbiased	31.367	31.256	-0.1107
46	5e+12	NDD unbiased	31.204	31.409	0.205
47	5e+12	NDD unbiased	31.075	31.229	0.1536
50	1e+13	NDD unbiased	31.571	31.898	0.3264
51	1e+13	NDD unbiased	30.662	30.849	0.1863
52	1e+13	NDD unbiased	31.162	31.357	0.1948
53	1e+13	NDD unbiased	30.908	31.175	0.2667

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	30.844	31.066	31.287	0.31282	31	31.037	31.074	0.052184	-0.2868	-0.0287	0.2294	0.36501
1e+12	30.839	31.15	31.435	0.24944	31.029	31.329	31.702	0.27925	-0.0713	0.17858	0.4197	0.21185
5e+12	31.075	31.3	31.553	0.20671	31.229	31.401	31.71	0.22069	-0.1107	0.10122	0.205	0.14322
1e+13	30.662	31.076	31.571	0.38823	30.849	31.32	31.898	0.43912	0.1863	0.24355	0.3264	0.065965

Device Test: 112.1 SW_T_HPHL_PWM(_Prop Delay HO Off PWM VIN_14V)





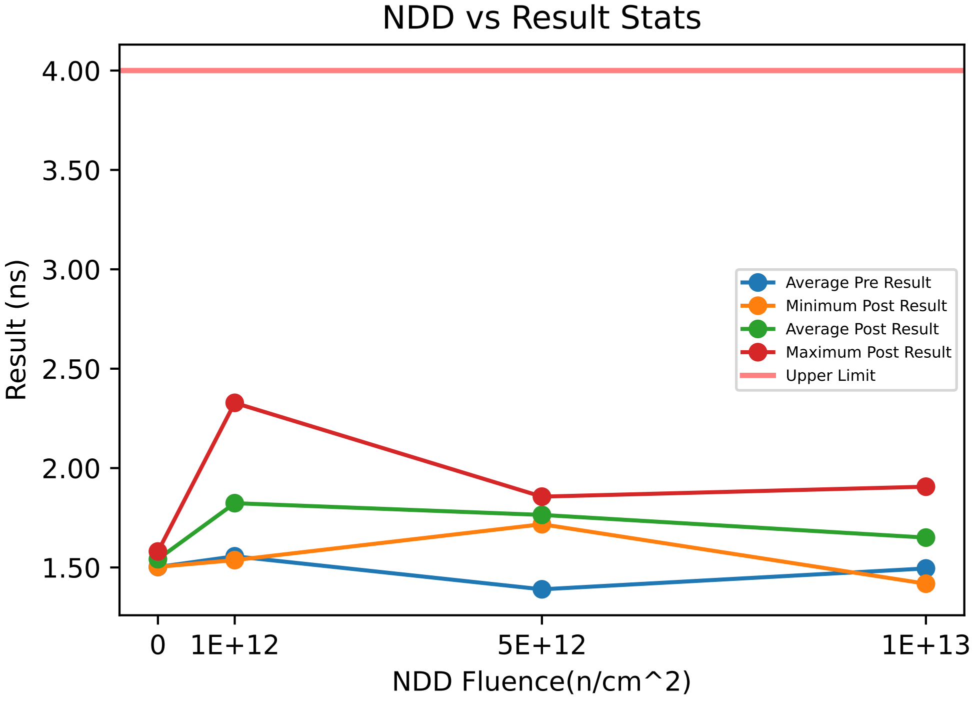
Test Results (Upper Limit = 50.0 (ns))

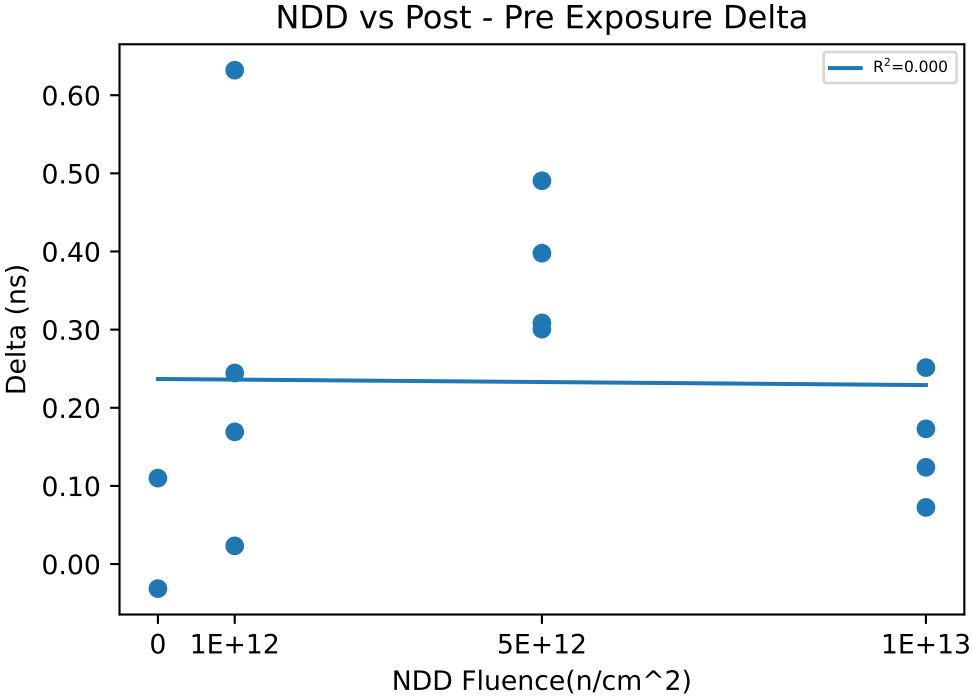
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	31.443	31.749	0.3059
2	0	Correlation	31.531	32.15	0.619
30	1e+12	NDD unbiased	31.504	32.212	0.7087
31	1e+12	NDD unbiased	31.901	31.908	0.0071
32	1e+12	NDD unbiased	32.378	32.781	0.4033
33	1e+12	NDD unbiased	31.916	32.226	0.3104
44	5e+12	NDD unbiased	31.832	32.16	0.3276
45	5e+12	NDD unbiased	31.802	32.094	0.2915
46	5e+12	NDD unbiased	31.976	32.302	0.3256
47	5e+12	NDD unbiased	31.715	32.079	0.3639
50	1e+13	NDD unbiased	32.283	32.618	0.3351
51	1e+13	NDD unbiased	31.539	31.9	0.3606
52	1e+13	NDD unbiased	31.947	32.267	0.3196
53	1e+13	NDD unbiased	31.706	32.033	0.3272

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	31.443	31.487	31.531	0.062367	31.749	31.95	32.15	0.28376	0.3059	0.46245	0.619	0.2214
1e+12	31.504	31.925	32.378	0.35747	31.908	32.282	32.781	0.36378	0.0071	0.35737	0.7087	0.28893
5e+12	31.715	31.831	31.976	0.10854	32.079	32.159	32.302	0.10174	0.2915	0.32715	0.3639	0.029575
1e+13	31.539	31.869	32.283	0.32276	31.9	32.204	32.618	0.31455	0.3196	0.33563	0.3606	0.017812

Device Test: 112.11 SW_T_MATCH_OFF(_Delay Match LO Off HO On IIM Interlock VIN_14V)


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

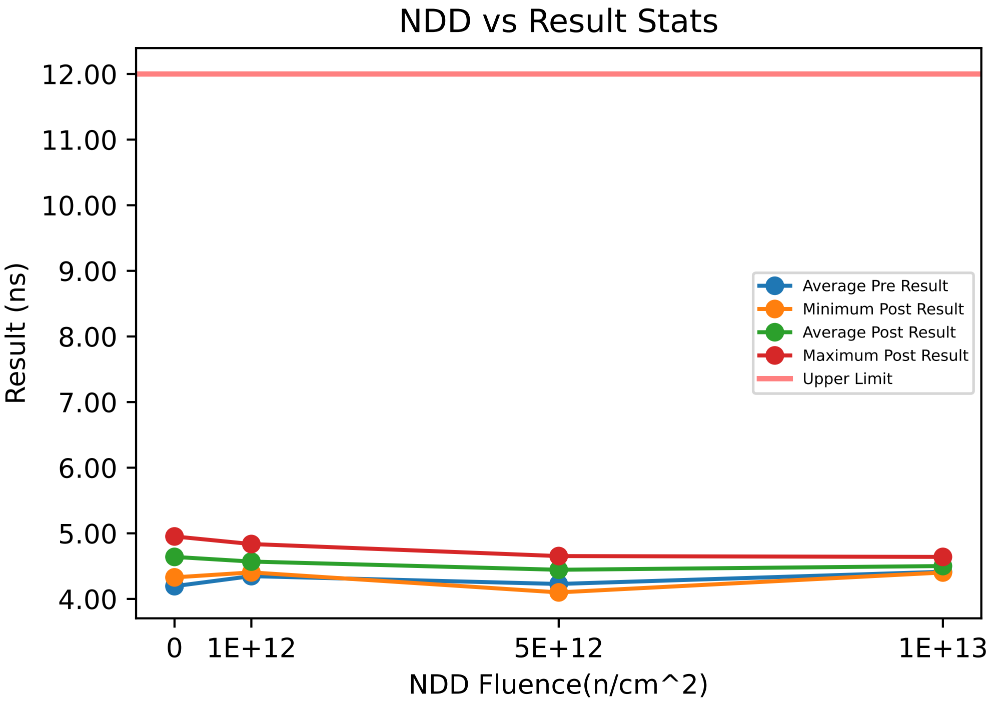
Test Results (Upper Limit = 4.0 (ns))

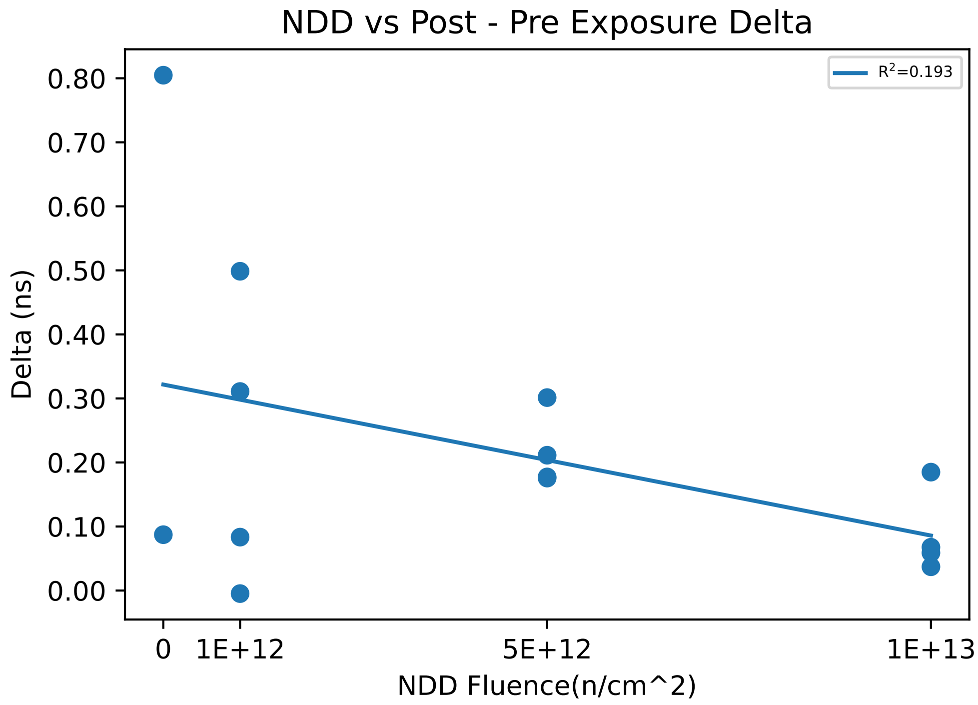
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	1.393	1.503	0.11
2	0	Correlation	1.6117	1.5803	-0.0314
30	1e+12	NDD unbiased	1.1954	1.8274	0.632
31	1e+12	NDD unbiased	1.5136	1.5369	0.0233
32	1e+12	NDD unbiased	1.3568	1.6013	0.2445
33	1e+12	NDD unbiased	2.1589	2.3281	0.1692
44	5e+12	NDD unbiased	1.4585	1.8563	0.3978
45	5e+12	NDD unbiased	1.2514	1.7419	0.4905
46	5e+12	NDD unbiased	1.4413	1.7419	0.3006
47	5e+12	NDD unbiased	1.4088	1.7174	0.3086
50	1e+13	NDD unbiased	1.7332	1.9063	0.1731
51	1e+13	NDD unbiased	1.1668	1.4182	0.2514
52	1e+13	NDD unbiased	1.5971	1.7209	0.1238
53	1e+13	NDD unbiased	1.483	1.5555	0.0725

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.393	1.5023	1.6117	0.15464	1.503	1.5416	1.5803	0.054659	-0.0314	0.0393	0.11	0.099985
1e+12	1.1954	1.5562	2.1589	0.42229	1.5369	1.8234	2.3281	0.35877	0.0233	0.26725	0.632	0.25993
5e+12	1.2514	1.39	1.4585	0.09467	1.7174	1.7644	1.8563	0.062362	0.3006	0.37438	0.4905	0.089075
1e+13	1.1668	1.495	1.7332	0.24154	1.4182	1.6502	1.9063	0.21085	0.0725	0.1552	0.2514	0.076158

Device Test: 112.12 SW_T_MATCH_ON(_Delay Match LO On HO Off IIM Interlock Disable VIN_14V)





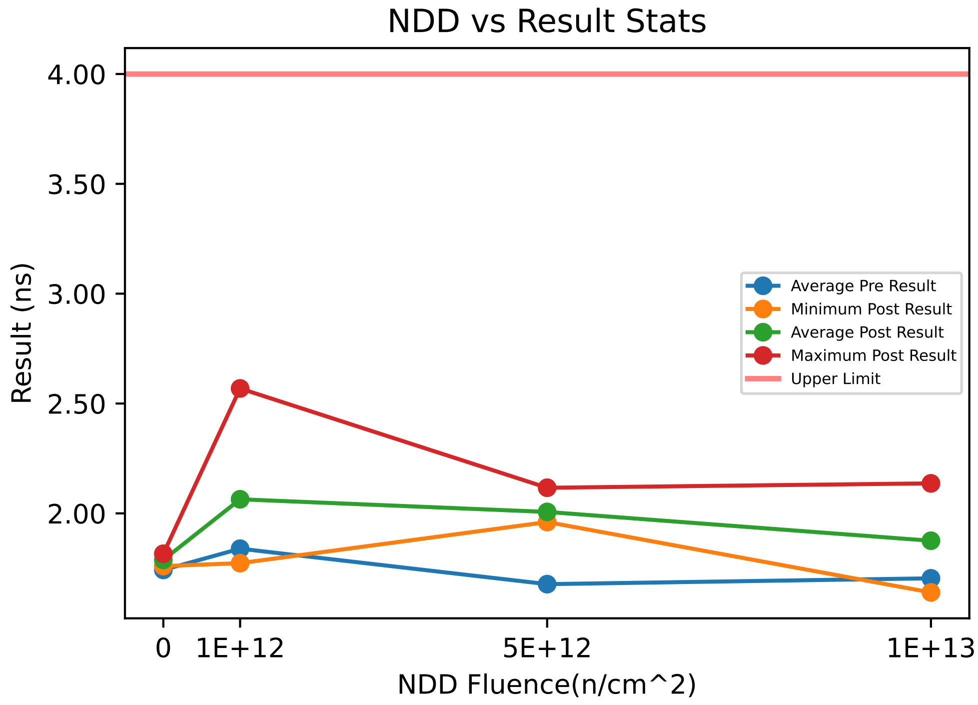
Test Results (Upper Limit = 12.0 (ns))

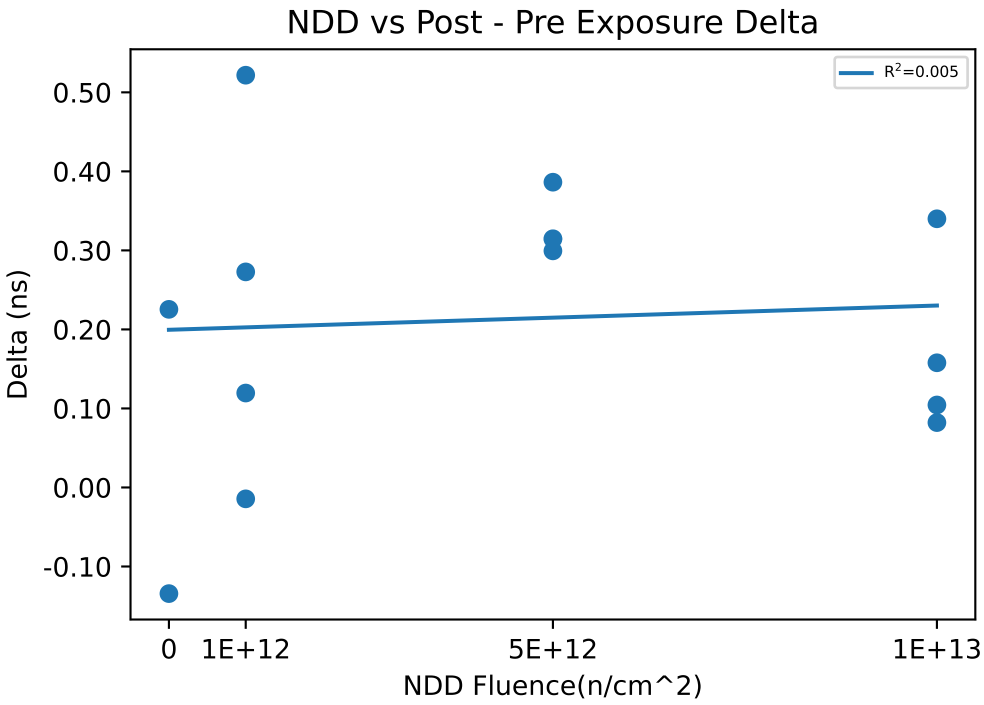
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	4.2413	4.3285	0.0872
2	0	Correlation	4.1475	4.9523	0.8048
30	1e+12	NDD unbiased	4.1192	4.6178	0.4986
31	1e+12	NDD unbiased	4.3209	4.4043	0.0834
32	1e+12	NDD unbiased	4.5259	4.8367	0.3108
33	1e+12	NDD unbiased	4.4244	4.4196	-0.0048
44	5e+12	NDD unbiased	3.924	4.0996	0.1756
45	5e+12	NDD unbiased	4.3093	4.5206	0.2113
46	5e+12	NDD unbiased	4.4758	4.6532	0.1774
47	5e+12	NDD unbiased	4.203	4.5043	0.3013
50	1e+13	NDD unbiased	4.5815	4.6404	0.0589
51	1e+13	NDD unbiased	4.2615	4.4464	0.1849
52	1e+13	NDD unbiased	4.4785	4.5156	0.0371
53	1e+13	NDD unbiased	4.3353	4.4029	0.0676

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.1475	4.1944	4.2413	0.066327	4.3285	4.6404	4.9523	0.44109	0.0872	0.446	0.8048	0.50742
1e+12	4.1192	4.3476	4.5259	0.17375	4.4043	4.5696	4.8367	0.20289	-0.0048	0.222	0.4986	0.22733
5e+12	3.924	4.228	4.4758	0.2317	4.0996	4.4444	4.6532	0.23936	0.1756	0.2164	0.3013	0.058934
1e+13	4.2615	4.4142	4.5815	0.14337	4.4029	4.5013	4.6404	0.10368	0.0371	0.087125	0.1849	0.066434

Device Test: 112.13 SW_T_MATCH_OFF(_Delay Match LO Off HO On IIM Interlock Disable VIN_14V)





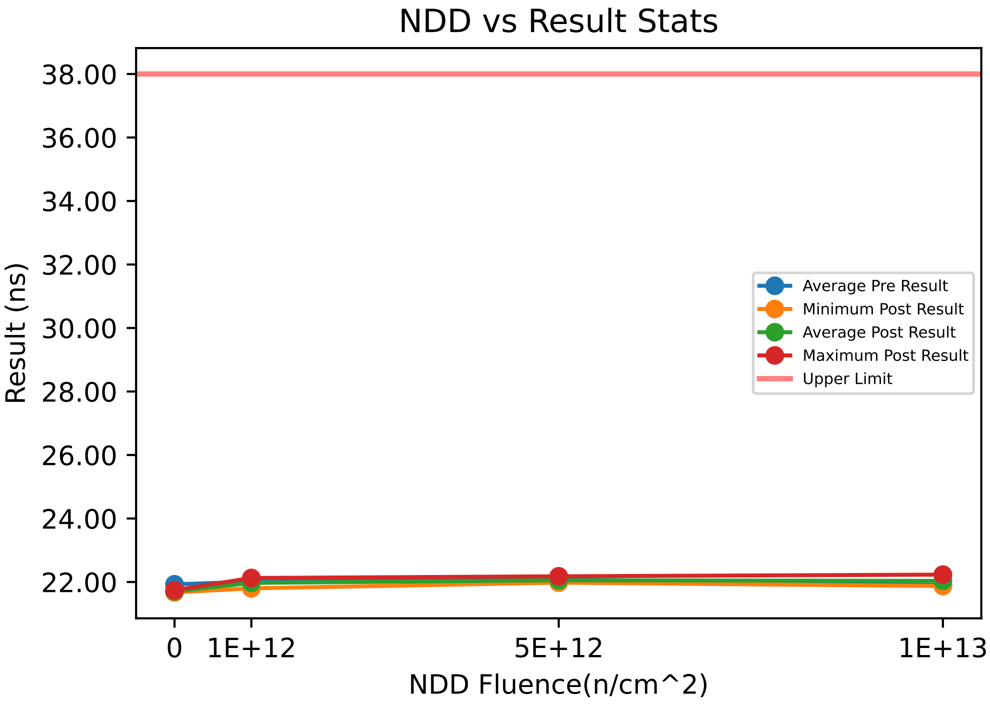
Test Results (Upper Limit = 4.0 (ns))

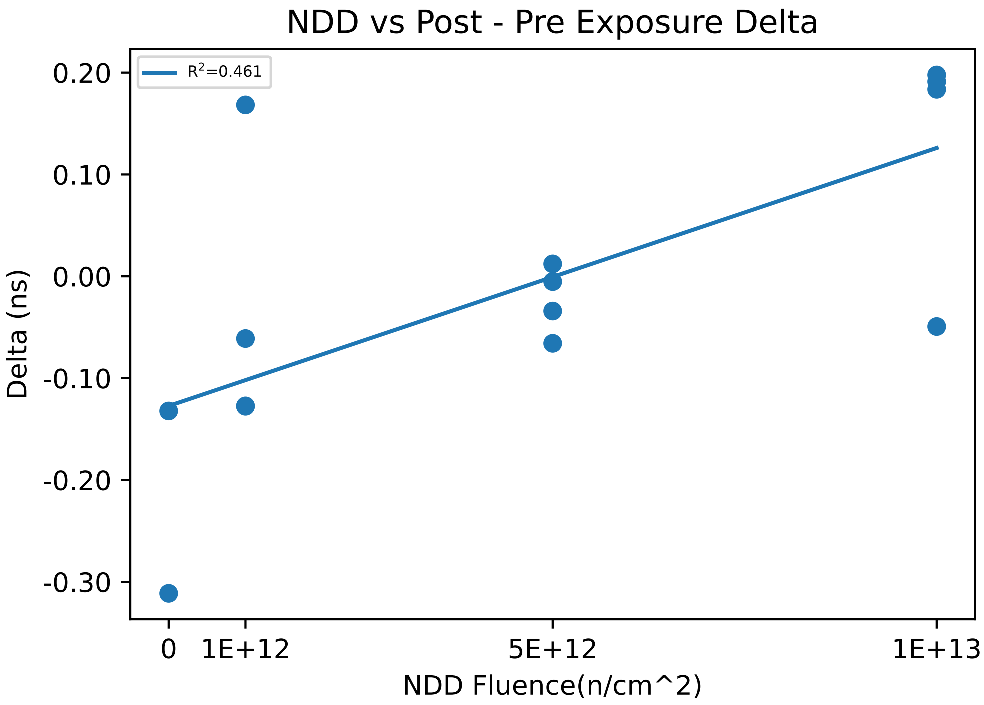
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	1.5346	1.76	0.2254
2	0	Correlation	1.9505	1.8162	-0.1343
30	1e+12	NDD unbiased	1.5525	2.0742	0.5217
31	1e+12	NDD unbiased	1.7878	1.7734	-0.0144
32	1e+12	NDD unbiased	1.5673	1.8401	0.2728
33	1e+12	NDD unbiased	2.4492	2.5687	0.1195
44	5e+12	NDD unbiased	1.8172	2.1166	0.2994
45	5e+12	NDD unbiased	1.6639	1.9786	0.3147
46	5e+12	NDD unbiased	1.6559	1.9704	0.3145
47	5e+12	NDD unbiased	1.5742	1.9605	0.3863
50	1e+13	NDD unbiased	2.0322	2.1366	0.1044
51	1e+13	NDD unbiased	1.3002	1.6402	0.34
52	1e+13	NDD unbiased	1.7913	1.9491	0.1578
53	1e+13	NDD unbiased	1.6935	1.7756	0.0821

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.5346	1.7426	1.9505	0.29409	1.76	1.7881	1.8162	0.039739	-0.1343	0.04555	0.2254	0.25435
1e+12	1.5525	1.8392	2.4492	0.42066	1.7734	2.0641	2.5687	0.36028	-0.0144	0.2249	0.5217	0.23004
5e+12	1.5742	1.6778	1.8172	0.10139	1.9605	2.0065	2.1166	0.073756	0.2994	0.32872	0.3863	0.039047
1e+13	1.3002	1.7043	2.0322	0.30469	1.6402	1.8754	2.1366	0.2152	0.0821	0.17108	0.34	0.11701

Device Test: 112.2 SW_T_LPLH_IIM(_Prop Delay LO On IIM Interlock VIN_14V)





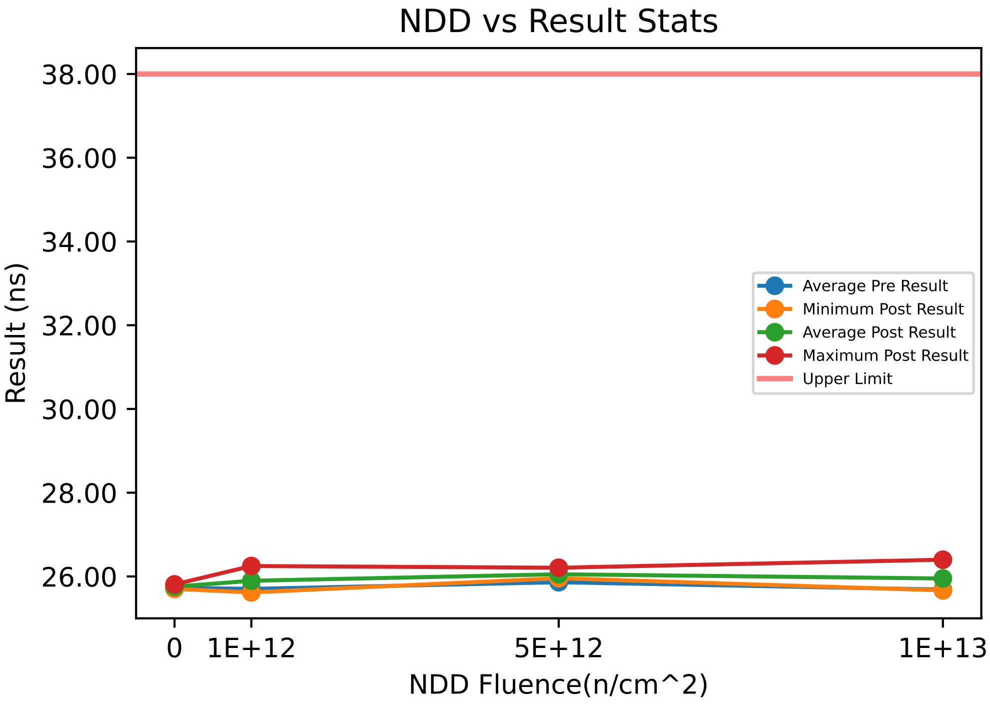
Test Results (Upper Limit = 38.0 (ns))

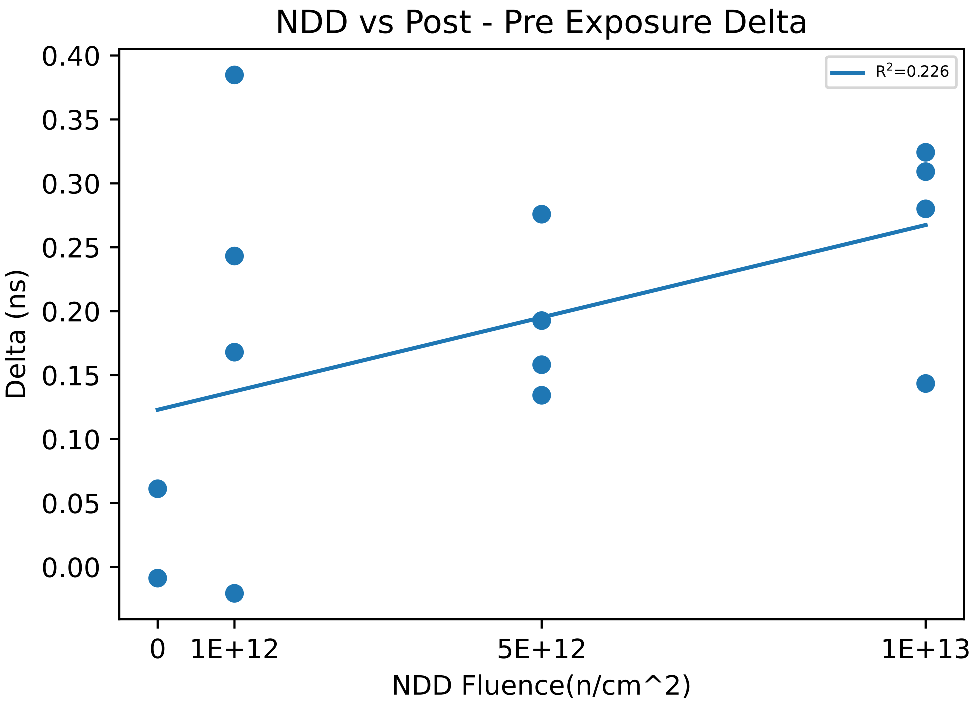
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	21.872	21.74	-0.1322
2	0	Correlation	21.984	21.672	-0.3113
30	1e+12	NDD unbiased	21.902	21.84	-0.0611
31	1e+12	NDD unbiased	21.928	21.8	-0.1276
32	1e+12	NDD unbiased	22.253	22.126	-0.1272
33	1e+12	NDD unbiased	21.952	22.121	0.1683
44	5e+12	NDD unbiased	22.213	22.179	-0.0341
45	5e+12	NDD unbiased	22.012	22.024	0.0122
46	5e+12	NDD unbiased	21.985	21.98	-0.0052
47	5e+12	NDD unbiased	22.104	22.038	-0.0658
50	1e+13	NDD unbiased	22.035	22.232	0.1977
51	1e+13	NDD unbiased	21.923	21.873	-0.0493
52	1e+13	NDD unbiased	21.963	22.147	0.1836
53	1e+13	NDD unbiased	21.697	21.888	0.1912

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	21.872	21.928	21.984	0.078772	21.672	21.706	21.74	0.047871	-0.3113	-0.22175	-0.1322	0.12664
1e+12	21.902	22.009	22.253	0.16434	21.8	21.972	22.126	0.17566	-0.1276	-0.0369	0.1683	0.14032
5e+12	21.985	22.078	22.213	0.10336	21.98	22.055	22.179	0.086353	-0.0658	-0.023225	0.0122	0.034209
1e+13	21.697	21.904	22.035	0.14576	21.873	22.035	22.232	0.18179	-0.0493	0.1308	0.1977	0.1202

Device Test: 112.3 SW_T_LPHL_IIM(_Prop Delay LO Off IIM Interlock VIN_14V)


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

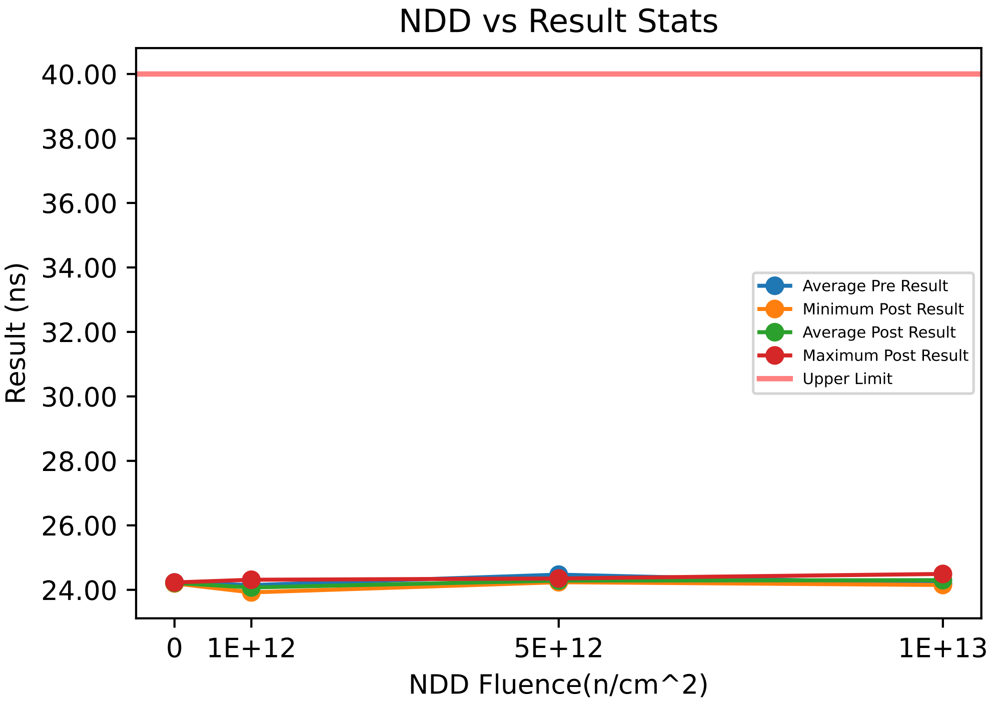
Test Results (Upper Limit = 38.0 (ns))

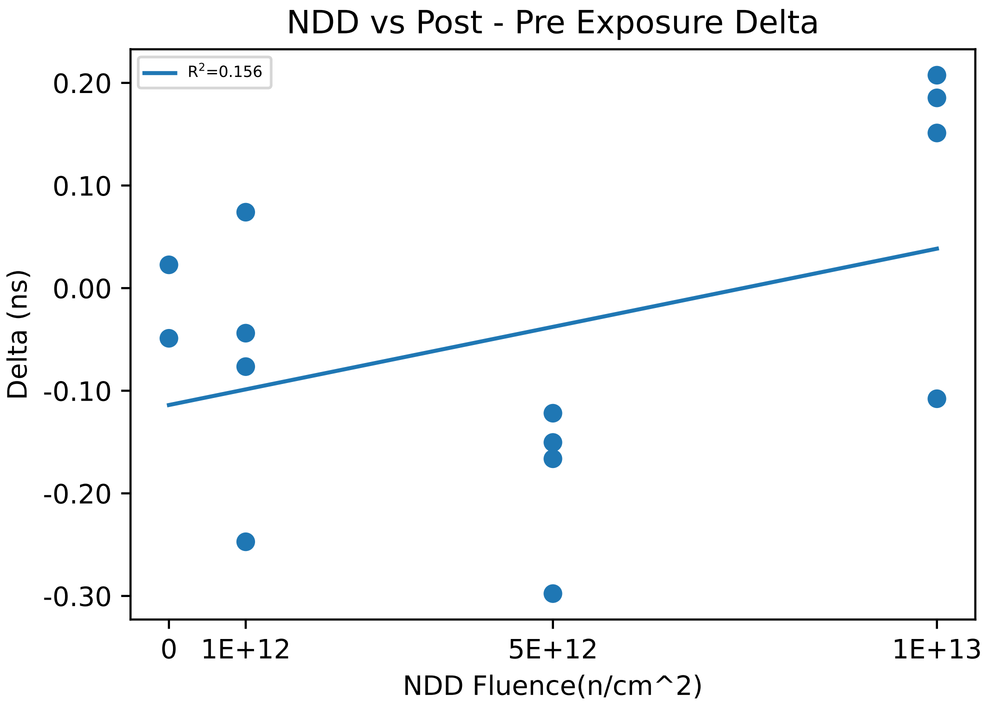
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	25.64	25.701	0.0612
2	0	Correlation	25.819	25.81	-0.0087
30	1e+12	NDD unbiased	25.419	25.804	0.3848
31	1e+12	NDD unbiased	25.639	25.619	-0.0206
32	1e+12	NDD unbiased	25.746	25.914	0.168
33	1e+12	NDD unbiased	26.006	26.249	0.2432
44	5e+12	NDD unbiased	25.932	26.208	0.2759
45	5e+12	NDD unbiased	25.786	25.979	0.1927
46	5e+12	NDD unbiased	25.93	26.064	0.1343
47	5e+12	NDD unbiased	25.798	25.957	0.1582
50	1e+13	NDD unbiased	26.075	26.399	0.3243
51	1e+13	NDD unbiased	25.523	25.667	0.1435
52	1e+13	NDD unbiased	25.723	26.032	0.3092
53	1e+13	NDD unbiased	25.426	25.706	0.2801

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	25.64	25.729	25.819	0.12608	25.701	25.756	25.81	0.07665	-0.0087	0.02625	0.0612	0.049427
1e+12	25.419	25.703	26.006	0.2436	25.619	25.896	26.249	0.26464	-0.0206	0.19385	0.3848	0.16887
5e+12	25.786	25.862	25.932	0.080275	25.957	26.052	26.208	0.11393	0.1343	0.19027	0.2759	0.061913
1e+13	25.426	25.687	26.075	0.28668	25.667	25.951	26.399	0.34063	0.1435	0.26427	0.3243	0.08258

Device Test: 112.4 SW_T_HPLH_IIM(_Prop Delay HO On IIM Interlock VIN_14V)





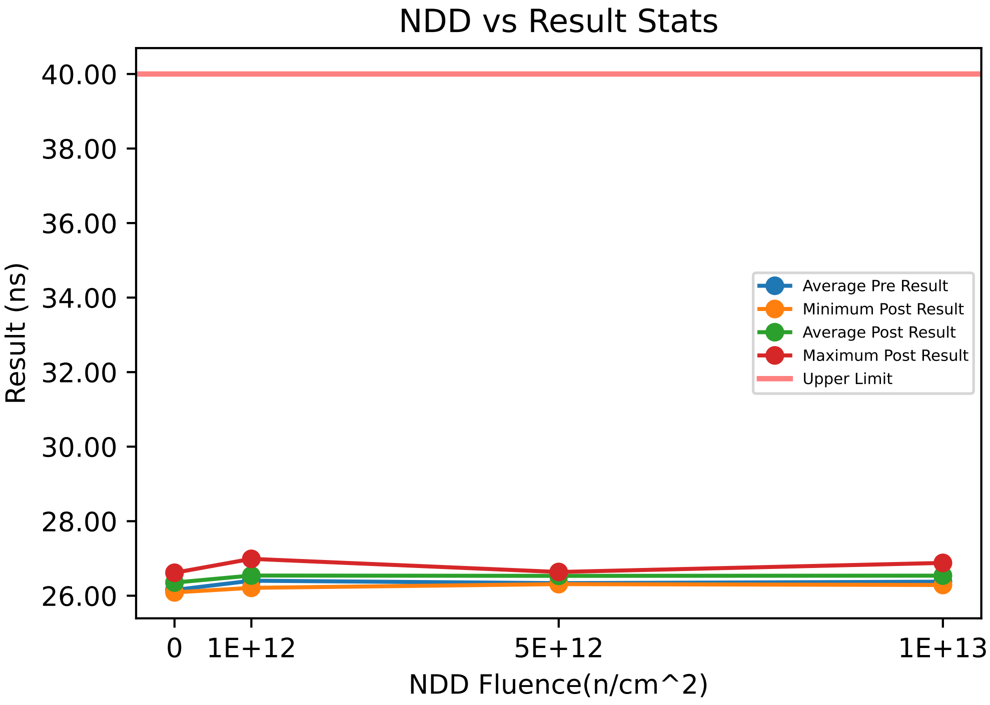
Test Results (Upper Limit = 40.0 (ns))

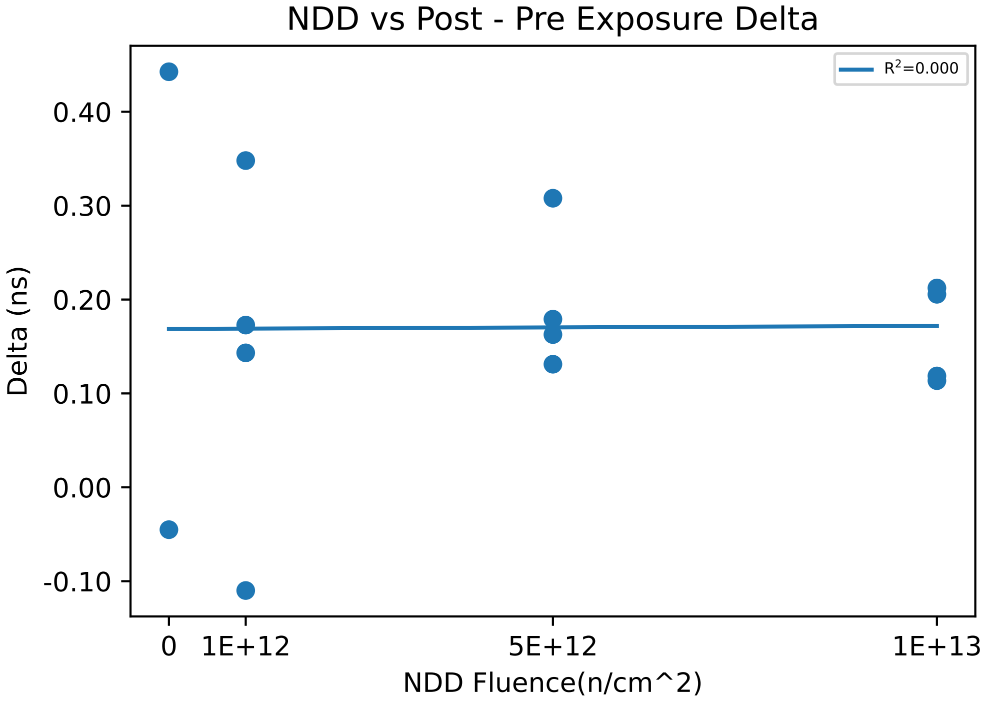
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	24.247	24.198	-0.0489
2	0	Correlation	24.207	24.23	0.0227
30	1e+12	NDD unbiased	24.224	23.977	-0.2472
31	1e+12	NDD unbiased	24.126	24.082	-0.0439
32	1e+12	NDD unbiased	24.389	24.313	-0.0765
33	1e+12	NDD unbiased	23.847	23.921	0.074
44	5e+12	NDD unbiased	24.474	24.352	-0.1219
45	5e+12	NDD unbiased	24.534	24.237	-0.2977
46	5e+12	NDD unbiased	24.488	24.322	-0.1663
47	5e+12	NDD unbiased	24.39	24.239	-0.1504
50	1e+13	NDD unbiased	24.342	24.493	0.1512
51	1e+13	NDD unbiased	24.356	24.249	-0.1078
52	1e+13	NDD unbiased	24.126	24.311	0.1854
53	1e+13	NDD unbiased	23.943	24.151	0.2075

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	24.207	24.227	24.247	0.028638	24.198	24.214	24.23	0.021991	-0.0489	-0.0131	0.0227	0.050629
1e+12	23.847	24.146	24.389	0.22751	23.921	24.073	24.313	0.17332	-0.2472	-0.0734	0.074	0.13268
5e+12	24.39	24.471	24.534	0.060435	24.237	24.287	24.352	0.058385	-0.2977	-0.18408	-0.1219	0.077945
1e+13	23.943	24.192	24.356	0.19644	24.151	24.301	24.493	0.14405	-0.1078	0.10907	0.2075	0.14643

Device Test: 112.5 SW_T_HPHL_IIM(_Prop Delay HO Off IIM Interlock VIN_14V)





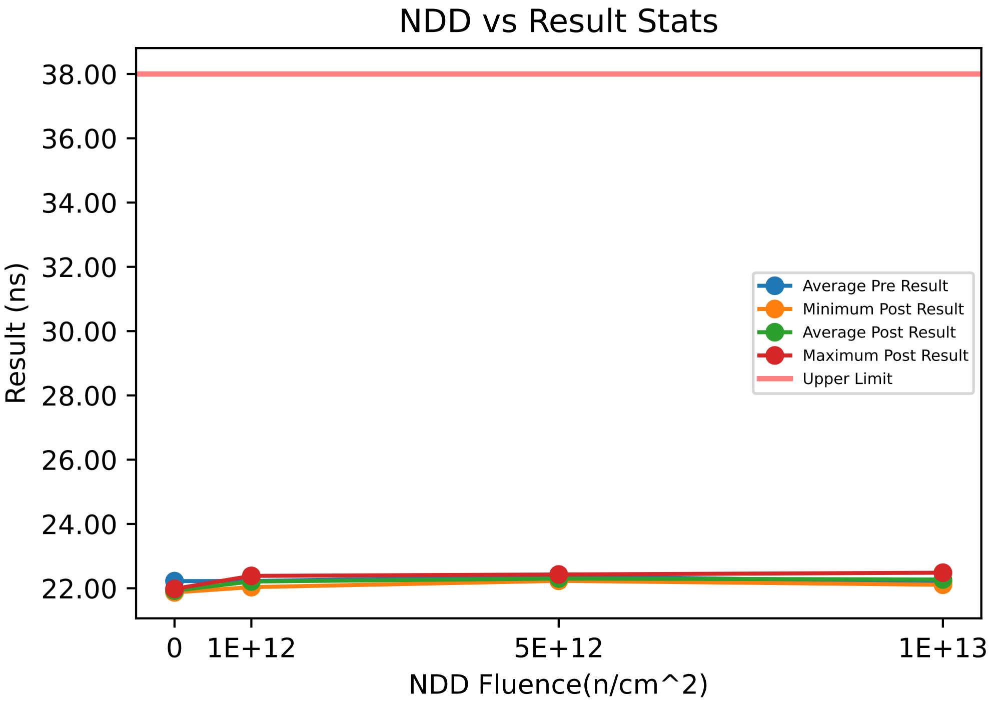
Test Results (Upper Limit = 40.0 (ns))

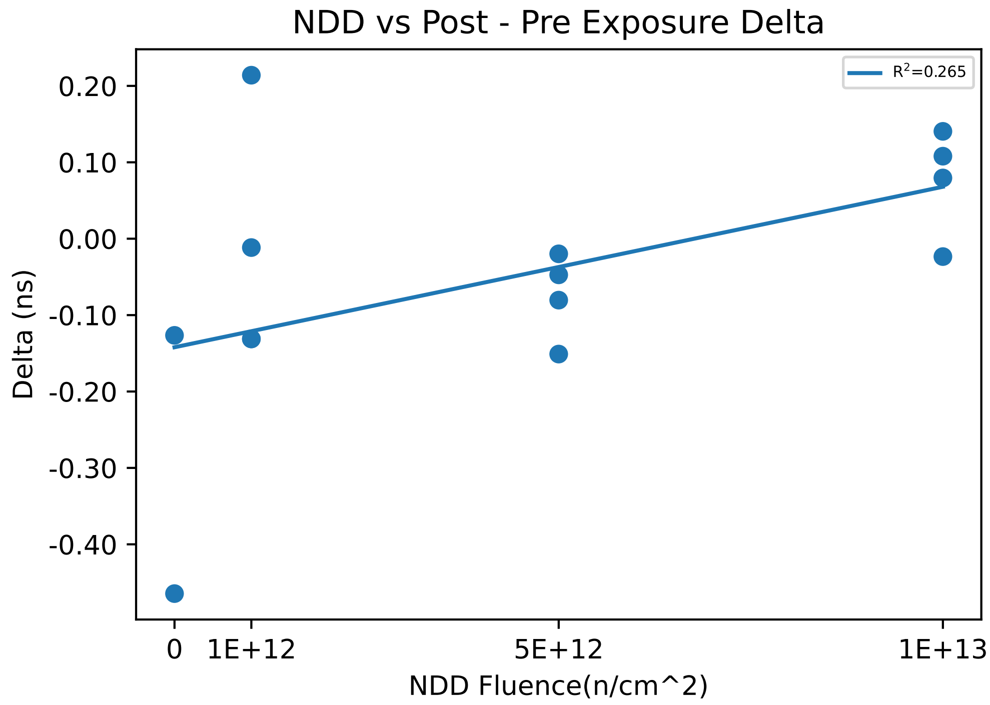
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	26.134	26.089	-0.0451
2	0	Correlation	26.173	26.616	0.4426
30	1e+12	NDD unbiased	26.11	26.458	0.348
31	1e+12	NDD unbiased	26.321	26.211	-0.1099
32	1e+12	NDD unbiased	26.817	26.989	0.1728
33	1e+12	NDD unbiased	26.363	26.506	0.1432
44	5e+12	NDD unbiased	26.148	26.311	0.1627
45	5e+12	NDD unbiased	26.29	26.598	0.3079
46	5e+12	NDD unbiased	26.458	26.637	0.1791
47	5e+12	NDD unbiased	26.455	26.586	0.1311
50	1e+13	NDD unbiased	26.762	26.88	0.1186
51	1e+13	NDD unbiased	26.214	26.328	0.1136
52	1e+13	NDD unbiased	26.446	26.658	0.2123
53	1e+13	NDD unbiased	26.082	26.288	0.2056

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	26.134	26.154	26.173	0.027648	26.089	26.352	26.616	0.3725	-0.0451	0.19875	0.4426	0.34486
1e+12	26.11	26.403	26.817	0.2972	26.211	26.541	26.989	0.32543	-0.1099	0.13853	0.348	0.18867
5e+12	26.148	26.338	26.458	0.14869	26.311	26.533	26.637	0.14963	0.1311	0.1952	0.3079	0.077729
1e+13	26.082	26.376	26.762	0.29781	26.288	26.539	26.88	0.28185	0.1136	0.16252	0.2123	0.053716

Device Test: 112.6 SW_T_LPLH_IIM(_Prop Delay LO On IIM Interlock Disable VIN_14V)





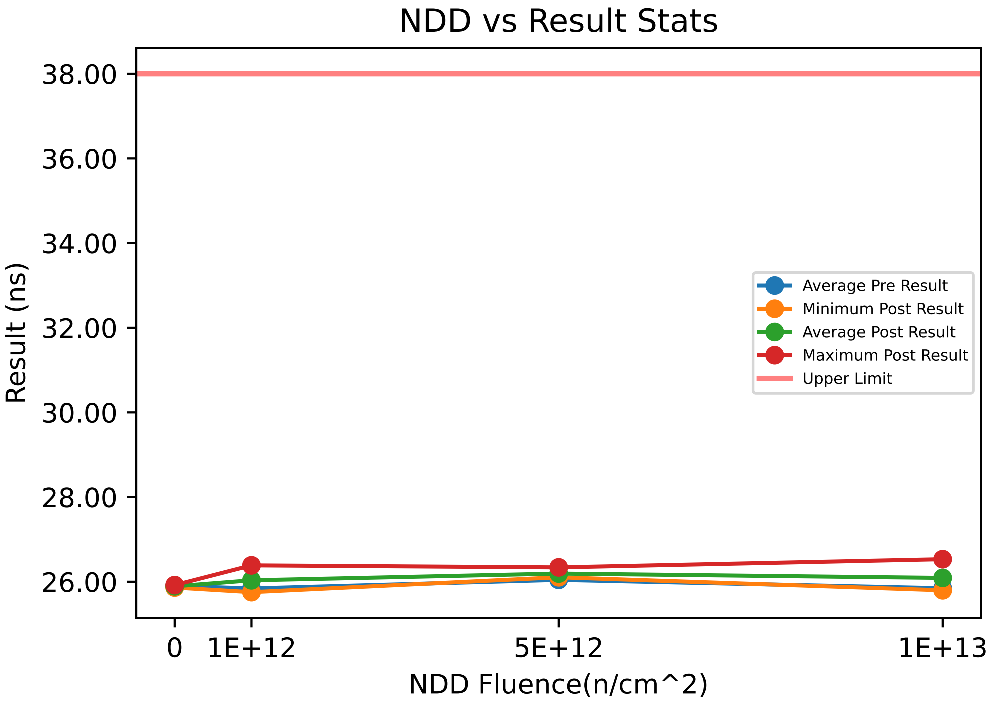
Test Results (Upper Limit = 38.0 (ns))

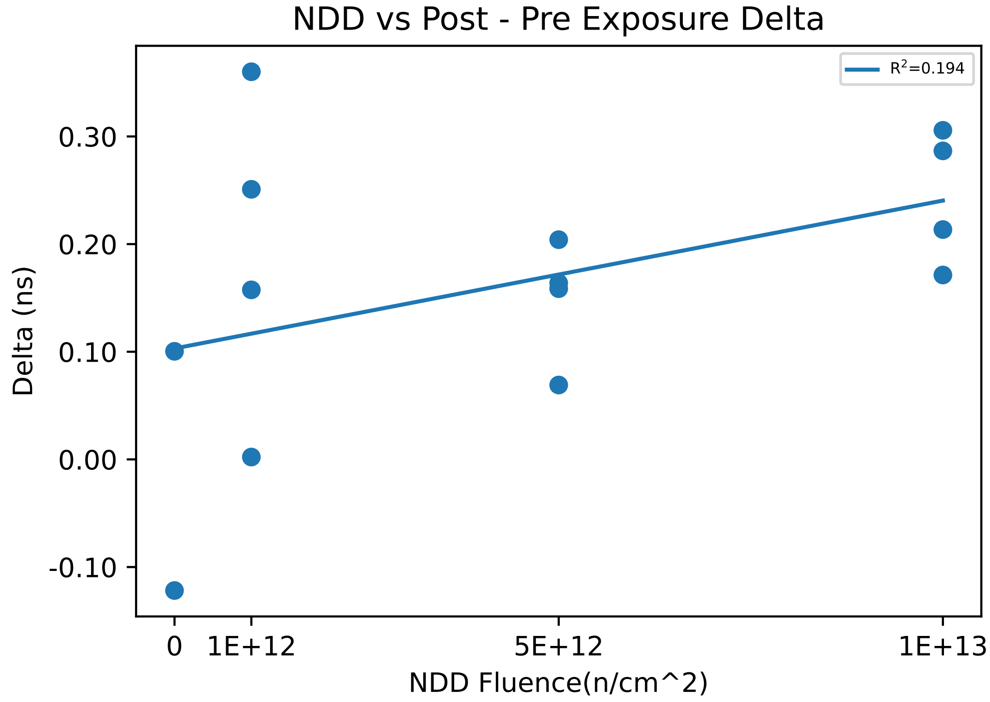
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	22.108	21.982	-0.1265
2	0	Correlation	22.336	21.871	-0.4645
30	1e+12	NDD unbiased	22.082	22.07	-0.0116
31	1e+12	NDD unbiased	22.166	22.035	-0.1311
32	1e+12	NDD unbiased	22.516	22.385	-0.1312
33	1e+12	NDD unbiased	22.135	22.349	0.214
44	5e+12	NDD unbiased	22.476	22.429	-0.0473
45	5e+12	NDD unbiased	22.289	22.269	-0.0198
46	5e+12	NDD unbiased	22.311	22.23	-0.0804
47	5e+12	NDD unbiased	22.426	22.275	-0.151
50	1e+13	NDD unbiased	22.343	22.484	0.1405
51	1e+13	NDD unbiased	22.154	22.131	-0.0234
52	1e+13	NDD unbiased	22.26	22.368	0.108
53	1e+13	NDD unbiased	22.029	22.109	0.0795

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	22.108	22.222	22.336	0.16073	21.871	21.926	21.982	0.078277	-0.4645	-0.2955	-0.1265	0.239
1e+12	22.082	22.225	22.516	0.19721	22.035	22.21	22.385	0.18274	-0.1312	-0.014975	0.214	0.16272
5e+12	22.289	22.376	22.476	0.090046	22.23	22.301	22.429	0.087456	-0.151	-0.074625	-0.0198	0.056624
1e+13	22.029	22.197	22.343	0.13579	22.109	22.273	22.484	0.18316	-0.0234	0.07615	0.1405	0.070891

Device Test: 112.7 SW_T_LPHL_IIM(_Prop Delay LO Off IIM Interlock Disable VIN_14V)





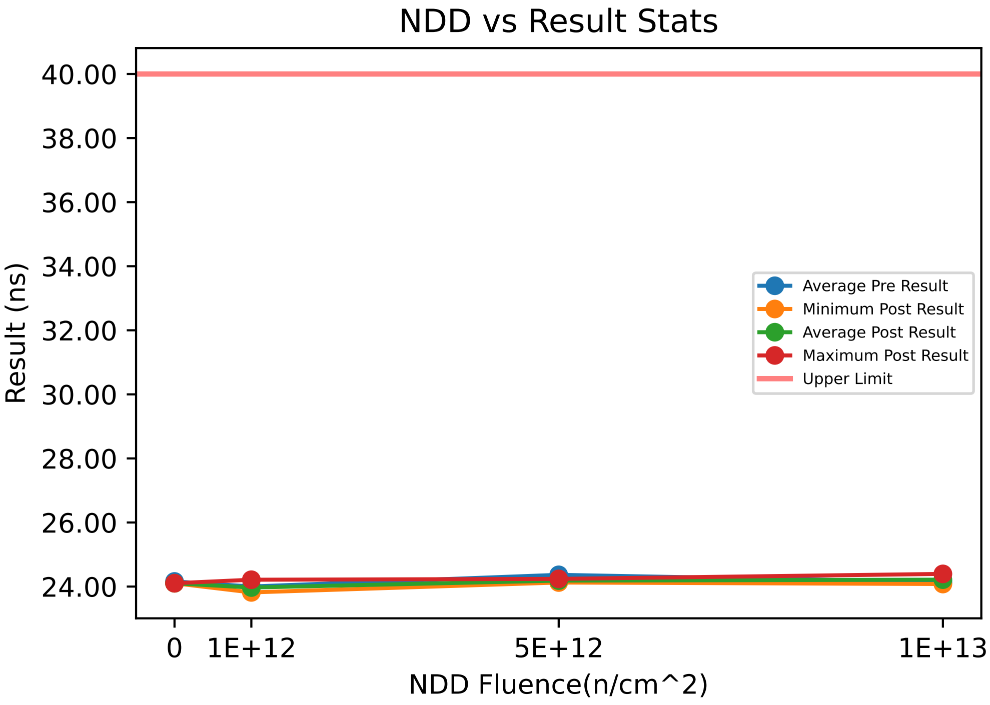
Test Results (Upper Limit = 38.0 (ns))

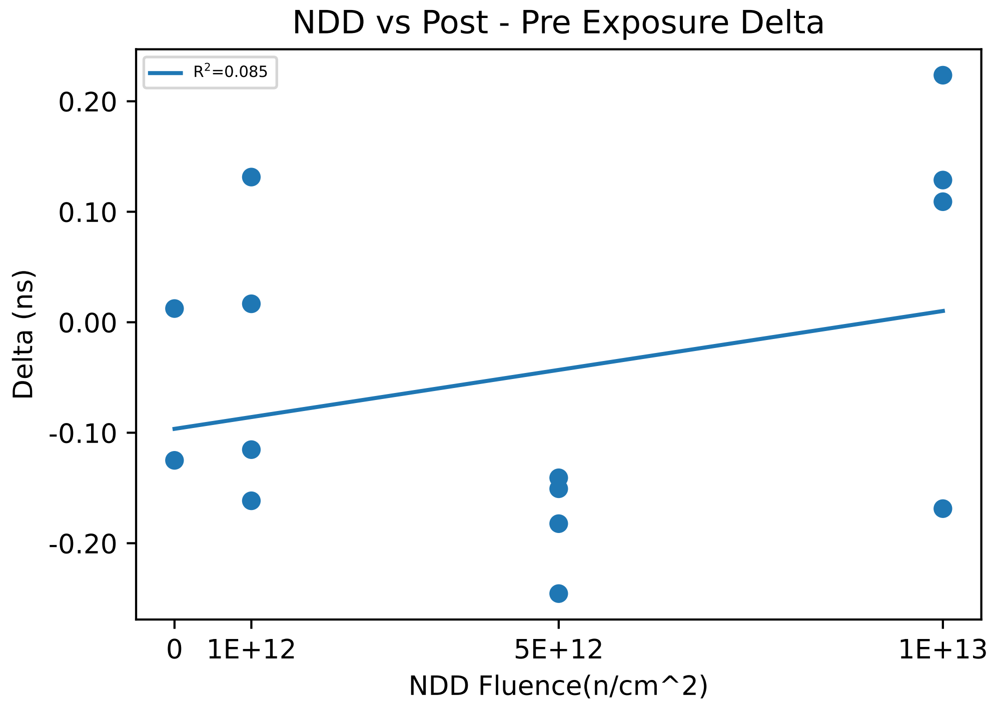
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	25.762	25.862	0.1004
2	0	Correlation	26.042	25.921	-0.1218
30	1e+12	NDD unbiased	25.581	25.941	0.3601
31	1e+12	NDD unbiased	25.751	25.754	0.0022
32	1e+12	NDD unbiased	25.896	26.053	0.1575
33	1e+12	NDD unbiased	26.136	26.387	0.2509
44	5e+12	NDD unbiased	26.18	26.339	0.1586
45	5e+12	NDD unbiased	26.036	26.105	0.0691
46	5e+12	NDD unbiased	26.046	26.21	0.1638
47	5e+12	NDD unbiased	25.913	26.117	0.2041
50	1e+13	NDD unbiased	26.319	26.532	0.2135
51	1e+13	NDD unbiased	25.626	25.798	0.1713
52	1e+13	NDD unbiased	25.892	26.179	0.2866
53	1e+13	NDD unbiased	25.549	25.855	0.3057

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	25.762	25.902	26.042	0.19827	25.862	25.892	25.921	0.041154	-0.1218	-0.0107	0.1004	0.15712
1e+12	25.581	25.841	26.136	0.23475	25.754	26.034	26.387	0.26574	0.0022	0.19267	0.3601	0.15159
5e+12	25.913	26.044	26.18	0.10913	26.105	26.193	26.339	0.10803	0.0691	0.1489	0.2041	0.056954
1e+13	25.549	25.846	26.319	0.34727	25.798	26.091	26.532	0.33864	0.1713	0.24428	0.3057	0.062814

Device Test: 112.8 SW_T_HPLH_IIM(_Prop Delay HO On IIM Interlock Disable VIN_14V)





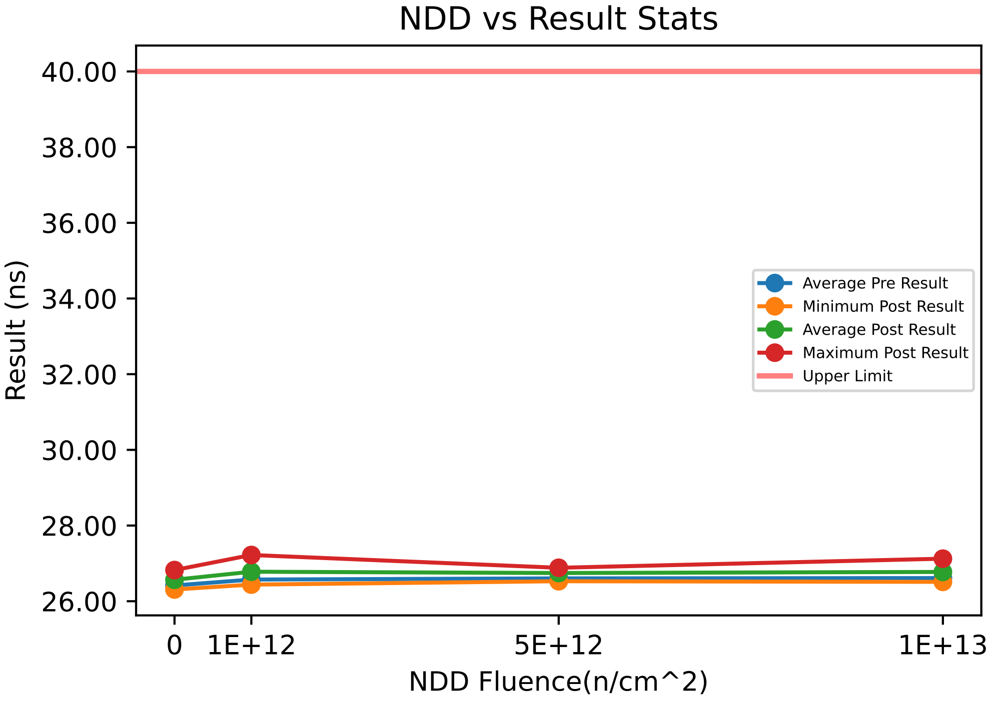
Test Results (Upper Limit = 40.0 (ns))

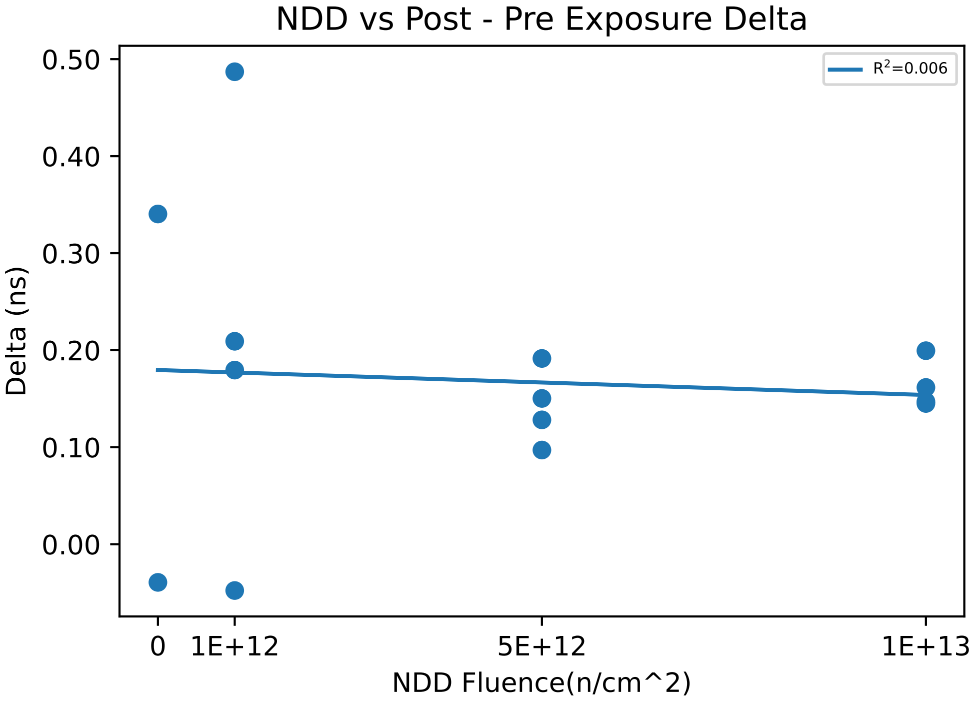
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	24.227	24.102	-0.125
2	0	Correlation	24.092	24.104	0.0124
30	1e+12	NDD unbiased	24.029	23.867	-0.1616
31	1e+12	NDD unbiased	23.964	23.98	0.0167
32	1e+12	NDD unbiased	24.329	24.213	-0.1153
33	1e+12	NDD unbiased	23.686	23.818	0.1314
44	5e+12	NDD unbiased	24.363	24.222	-0.1408
45	5e+12	NDD unbiased	24.372	24.126	-0.2456
46	5e+12	NDD unbiased	24.39	24.239	-0.1507
47	5e+12	NDD unbiased	24.339	24.157	-0.1823
50	1e+13	NDD unbiased	24.286	24.395	0.1091
51	1e+13	NDD unbiased	24.326	24.157	-0.1687
52	1e+13	NDD unbiased	24.101	24.229	0.1287
53	1e+13	NDD unbiased	23.856	24.079	0.2236

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	24.092	24.16	24.227	0.095813	24.102	24.103	24.104	0.0013435	-0.125	-0.0563	0.0124	0.097156
1e+12	23.686	24.002	24.329	0.2636	23.818	23.97	24.213	0.17612	-0.1616	-0.0322	0.1314	0.13267
5e+12	24.339	24.366	24.39	0.021213	24.126	24.186	24.239	0.053422	-0.2456	-0.17985	-0.1408	0.047271
1e+13	23.856	24.142	24.326	0.2148	24.079	24.215	24.395	0.13475	-0.1687	0.073175	0.2236	0.16882

Device Test: 112.9 SW_T_HPHL_IIM(_Prop Delay HO Off IIM Interlock Disable VIN_14V)





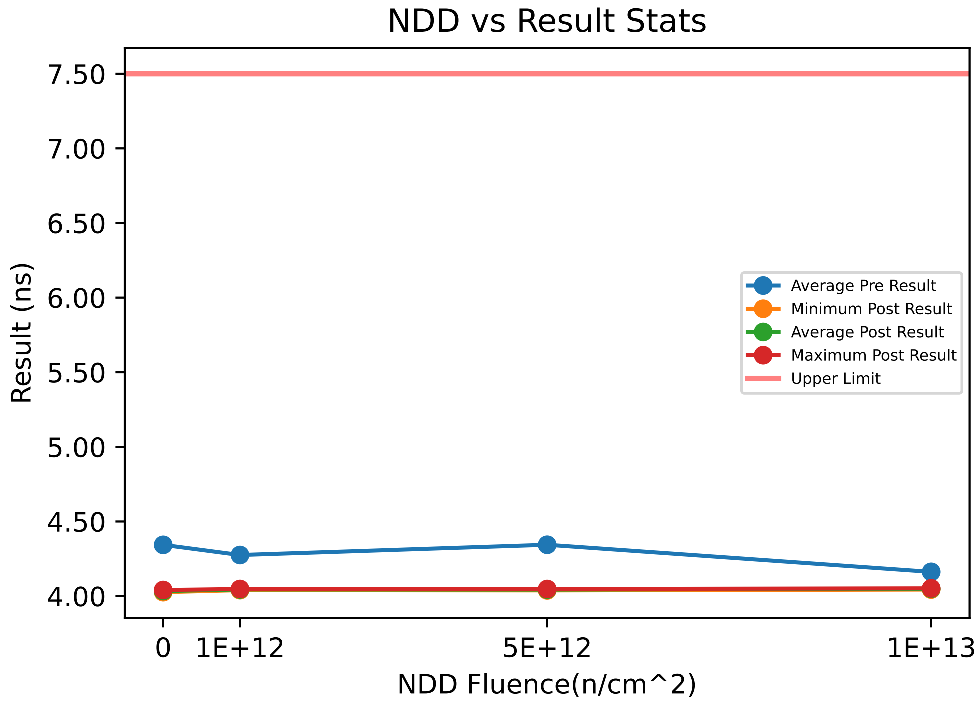
Test Results (Upper Limit = 40.0 (ns))

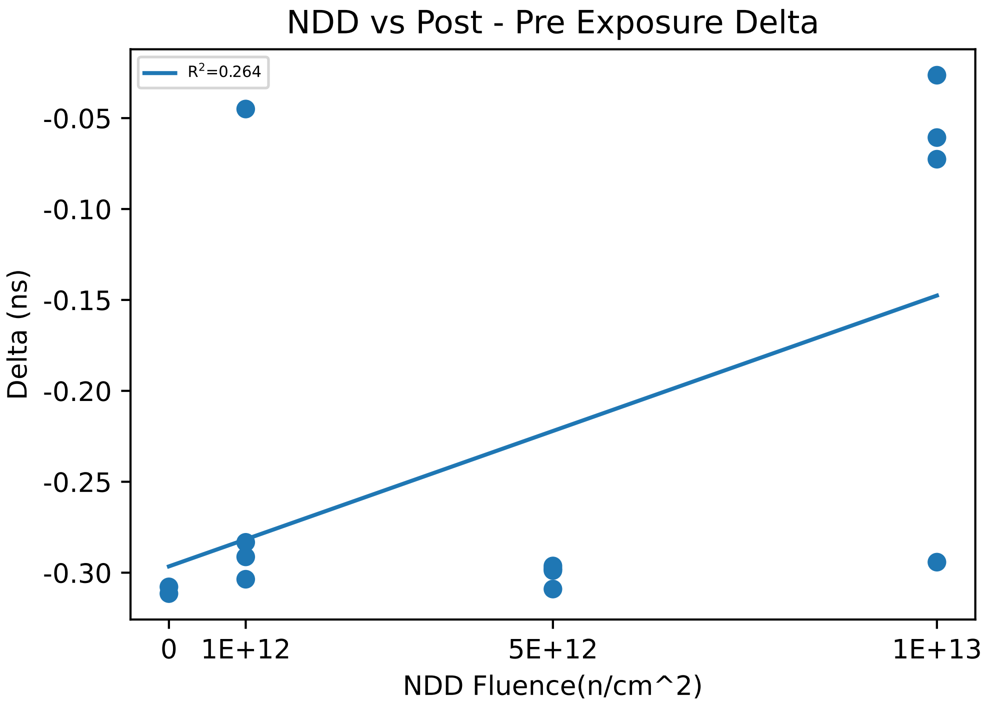
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	26.35	26.31	-0.0393
2	0	Correlation	26.483	26.823	0.3404
30	1e+12	NDD unbiased	26.201	26.688	0.487
31	1e+12	NDD unbiased	26.487	26.439	-0.0477
32	1e+12	NDD unbiased	27.042	27.222	0.1795
33	1e+12	NDD unbiased	26.56	26.769	0.2092
44	5e+12	NDD unbiased	26.4	26.528	0.1282
45	5e+12	NDD unbiased	26.599	26.79	0.1915
46	5e+12	NDD unbiased	26.787	26.884	0.0971
47	5e+12	NDD unbiased	26.629	26.78	0.1503
50	1e+13	NDD unbiased	26.924	27.124	0.1995
51	1e+13	NDD unbiased	26.416	26.577	0.1616
52	1e+13	NDD unbiased	26.739	26.884	0.1451
53	1e+13	NDD unbiased	26.365	26.512	0.1471

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	26.35	26.416	26.483	0.094328	26.31	26.567	26.823	0.36282	-0.0393	0.15055	0.3404	0.26849
1e+12	26.201	26.573	27.042	0.3492	26.439	26.78	27.222	0.32647	-0.0477	0.207	0.487	0.21911
5e+12	26.4	26.604	26.787	0.1587	26.528	26.745	26.884	0.15209	0.0971	0.14177	0.1915	0.039688
1e+13	26.365	26.611	26.924	0.26678	26.512	26.774	27.124	0.28408	0.1451	0.16333	0.1995	0.025212

Device Test: 115.0 SW_T_HRC(_Rise Time HO VIN_10V)





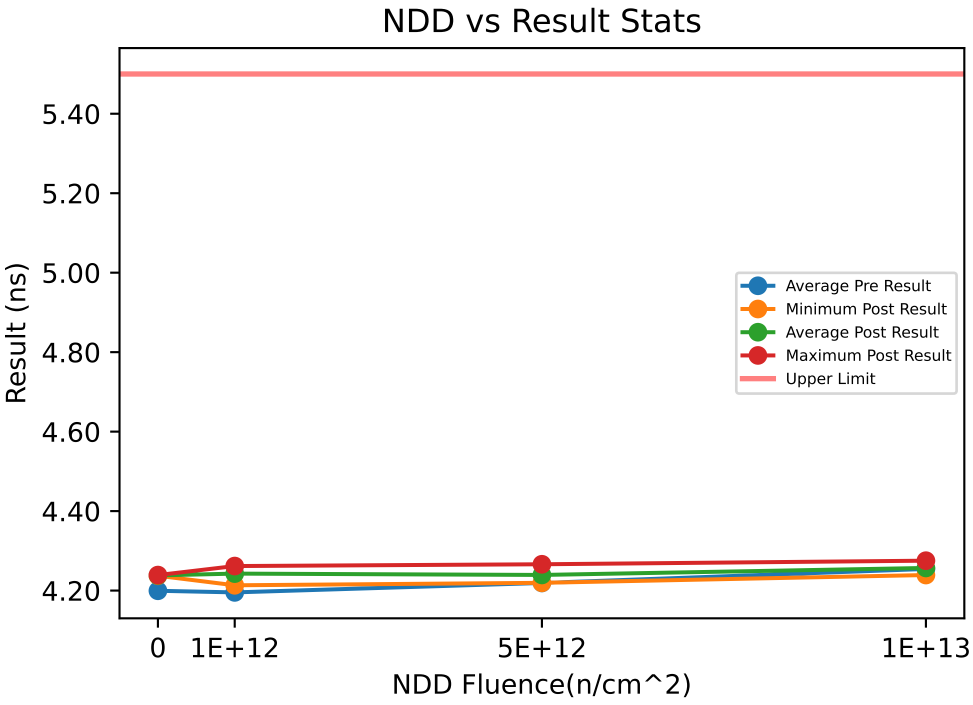
Test Results (Upper Limit = 7.5 (ns))

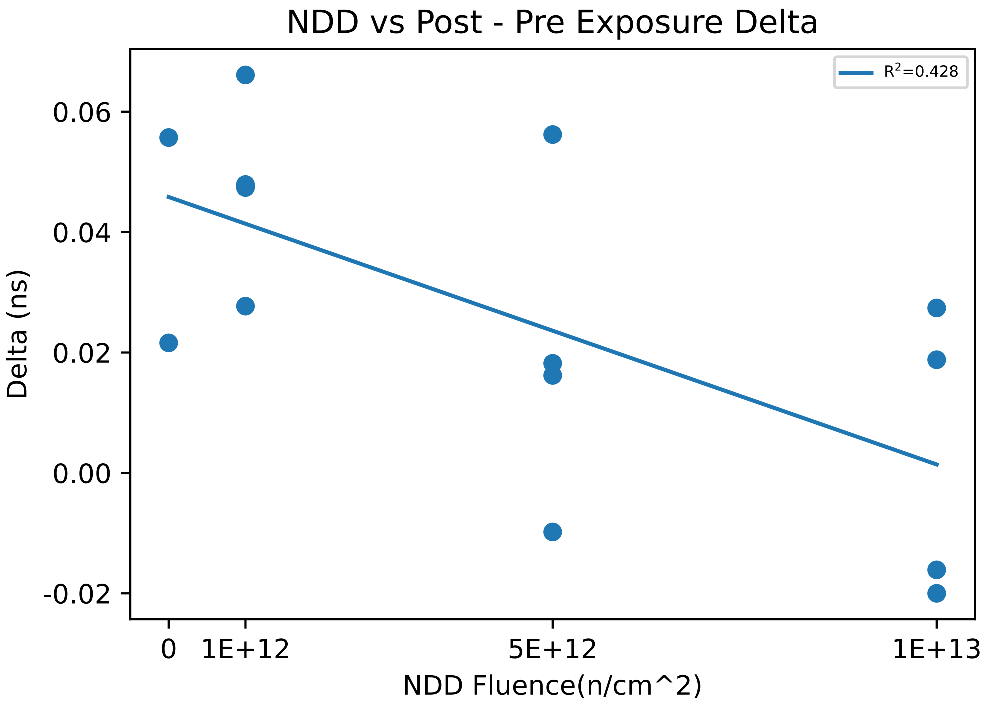
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	4.3525	4.041	-0.3115
2	0	Correlation	4.3343	4.0265	-0.3078
30	1e+12	NDD unbiased	4.3281	4.0448	-0.2833
31	1e+12	NDD unbiased	4.3436	4.04	-0.3036
32	1e+12	NDD unbiased	4.3373	4.046	-0.2913
33	1e+12	NDD unbiased	4.0928	4.0478	-0.045
44	5e+12	NDD unbiased	4.3473	4.0383	-0.309
45	5e+12	NDD unbiased	4.3402	4.0439	-0.2963
46	5e+12	NDD unbiased	4.3421	4.0443	-0.2978
47	5e+12	NDD unbiased	4.3465	4.0477	-0.2988
50	1e+13	NDD unbiased	4.0786	4.0522	-0.0264
51	1e+13	NDD unbiased	4.3382	4.044	-0.2942
52	1e+13	NDD unbiased	4.1101	4.0494	-0.0607
53	1e+13	NDD unbiased	4.1232	4.0506	-0.0726

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.3343	4.3434	4.3525	0.012869	4.0265	4.0338	4.041	0.010253	-0.3115	-0.30965	-0.3078	0.0026163
1e+12	4.0928	4.2755	4.3436	0.12193	4.04	4.0446	4.0478	0.0033362	-0.3036	-0.2308	-0.045	0.12415
5e+12	4.3402	4.344	4.3473	0.0034248	4.0383	4.0435	4.0477	0.0038932	-0.309	-0.30048	-0.2963	0.0057755
1e+13	4.0786	4.1625	4.3382	0.1186	4.044	4.0491	4.0522	0.0035567	-0.2942	-0.11347	-0.0264	0.12206

Device Test: 115.1 SW_T_HFC(_Fall Time HO VIN_10V)





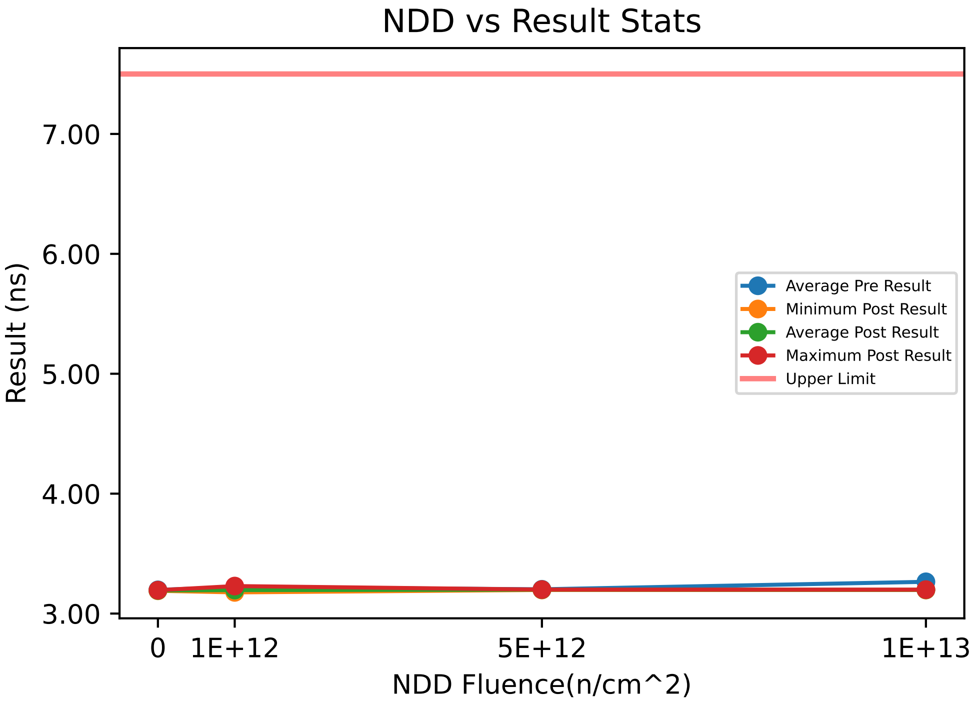
Test Results (Upper Limit = 5.5 (ns))

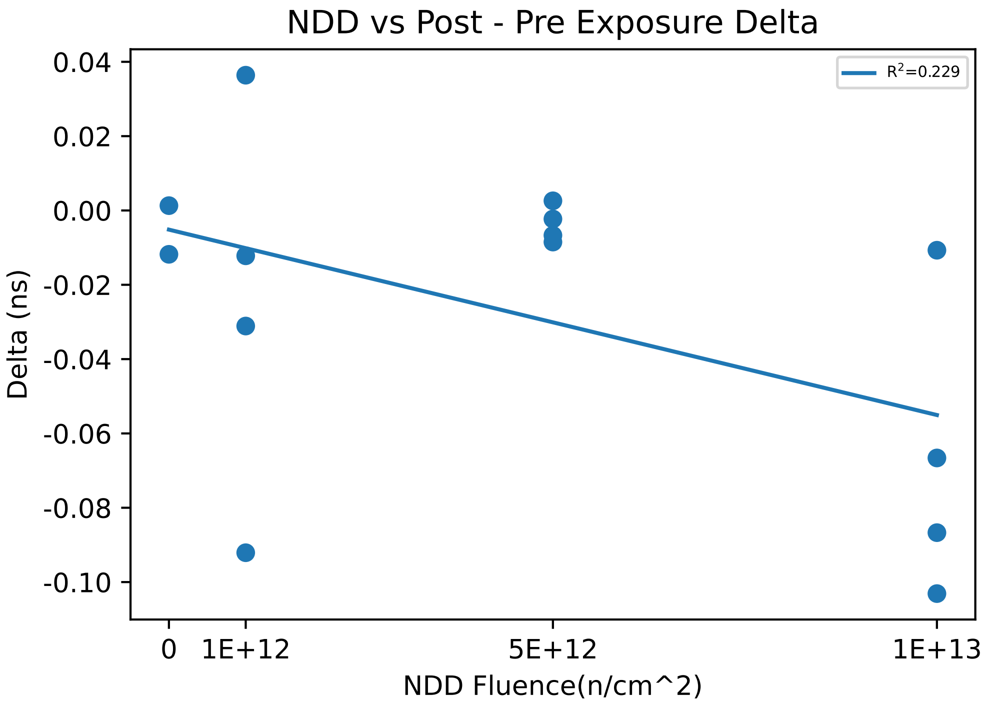
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	4.2174	4.239	0.0216
2	0	Correlation	4.1816	4.2373	0.0557
30	1e+12	NDD unbiased	4.1932	4.2593	0.0661
31	1e+12	NDD unbiased	4.2143	4.2617	0.0474
32	1e+12	NDD unbiased	4.1856	4.2133	0.0277
33	1e+12	NDD unbiased	4.1885	4.2364	0.0479
44	5e+12	NDD unbiased	4.21	4.2662	0.0562
45	5e+12	NDD unbiased	4.2293	4.2195	-0.0098
46	5e+12	NDD unbiased	4.2321	4.2503	0.0182
47	5e+12	NDD unbiased	4.2051	4.2213	0.0162
50	1e+13	NDD unbiased	4.2203	4.2391	0.0188
51	1e+13	NDD unbiased	4.2319	4.2593	0.0274
52	1e+13	NDD unbiased	4.2741	4.2541	-0.02
53	1e+13	NDD unbiased	4.2913	4.2752	-0.0161

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.1816	4.1995	4.2174	0.025314	4.2373	4.2382	4.239	0.0012021	0.0216	0.03865	0.0557	0.024112
1e+12	4.1856	4.1954	4.2143	0.012983	4.2133	4.2427	4.2617	0.022661	0.0277	0.047275	0.0661	0.015684
5e+12	4.2051	4.2191	4.2321	0.013563	4.2195	4.2393	4.2662	0.022808	-0.0098	0.0202	0.0562	0.027178
1e+13	4.2203	4.2544	4.2913	0.033758	4.2391	4.2569	4.2752	0.014892	-0.02	0.002525	0.0274	0.024069

Device Test: 115.2 SW_T_LRC(_Rise Time LO VIN_10V)


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

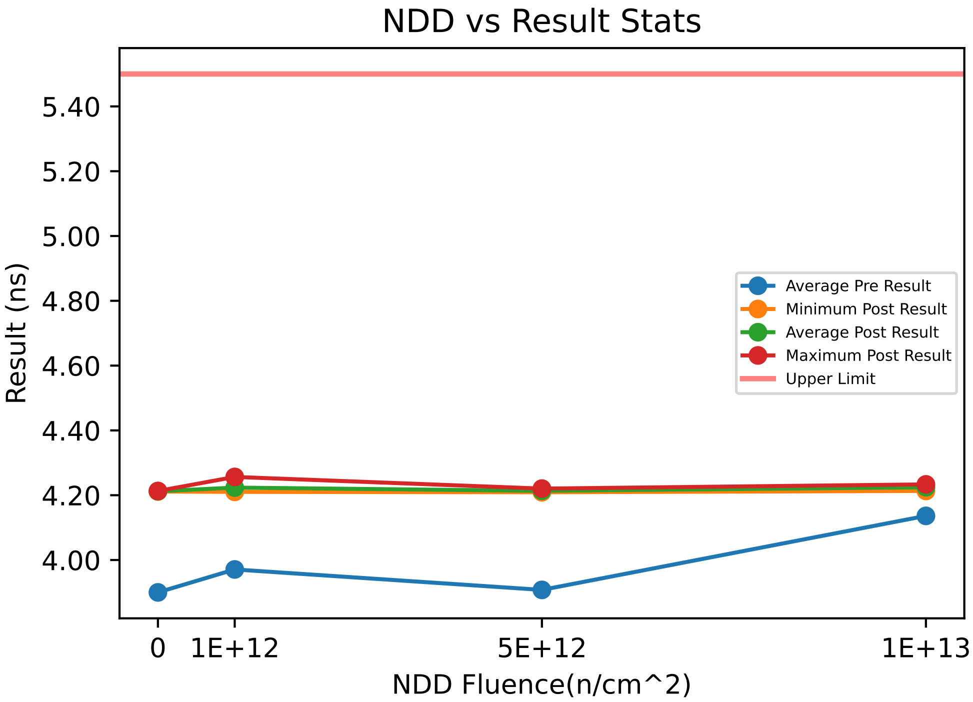
Test Results (Upper Limit = 7.5 (ns))

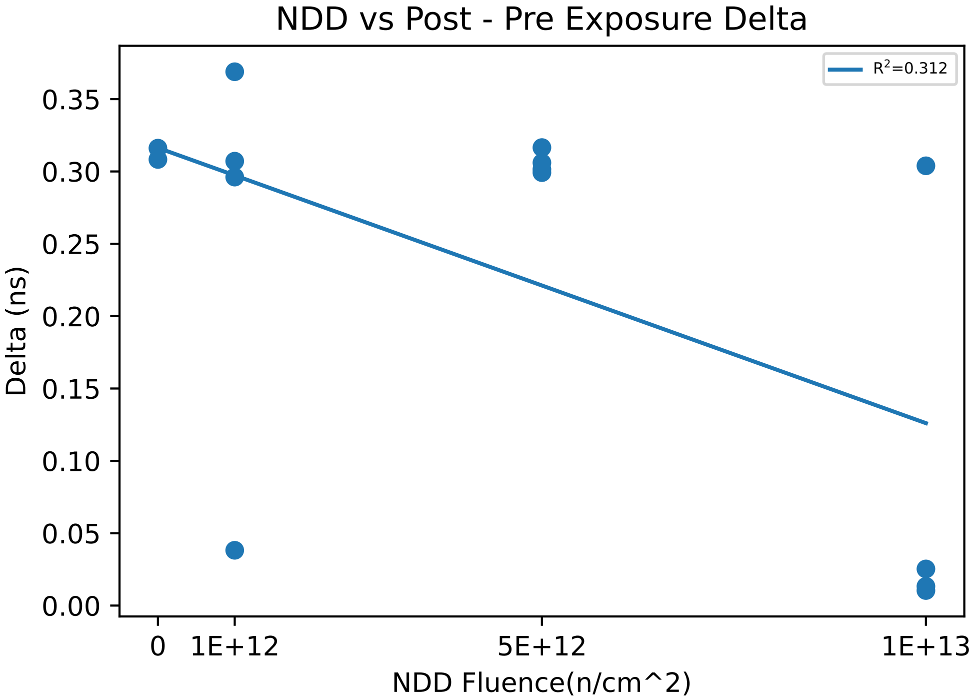
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	3.1935	3.1948	0.0013
2	0	Correlation	3.2019	3.1901	-0.0118
30	1e+12	NDD unbiased	3.193	3.2294	0.0364
31	1e+12	NDD unbiased	3.2076	3.1765	-0.0311
32	1e+12	NDD unbiased	3.2047	3.1925	-0.0122
33	1e+12	NDD unbiased	3.2768	3.1847	-0.0921
44	5e+12	NDD unbiased	3.2068	3.2001	-0.0067
45	5e+12	NDD unbiased	3.2011	3.1988	-0.0023
46	5e+12	NDD unbiased	3.1943	3.1969	0.0026
47	5e+12	NDD unbiased	3.2076	3.1991	-0.0085
50	1e+13	NDD unbiased	3.2863	3.1996	-0.0867
51	1e+13	NDD unbiased	3.2081	3.1974	-0.0107
52	1e+13	NDD unbiased	3.2653	3.1987	-0.0666
53	1e+13	NDD unbiased	3.2995	3.1964	-0.1031

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.1935	3.1977	3.2019	0.0059397	3.1901	3.1925	3.1948	0.0033234	-0.0118	-0.00525	0.0013	0.0092631
1e+12	3.193	3.2205	3.2768	0.038044	3.1765	3.1958	3.2294	0.023349	-0.0921	-0.02475	0.0364	0.053145
5e+12	3.1943	3.2024	3.2076	0.006156	3.1969	3.1987	3.2001	0.0013376	-0.0085	-0.003725	0.0026	0.0049561
1e+13	3.2081	3.2648	3.2995	0.040338	3.1964	3.198	3.1996	0.0014104	-0.1031	-0.066775	-0.0107	0.040253

Device Test: 115.3 SW_T_LFC(_Fall Time LO VIN_10V)





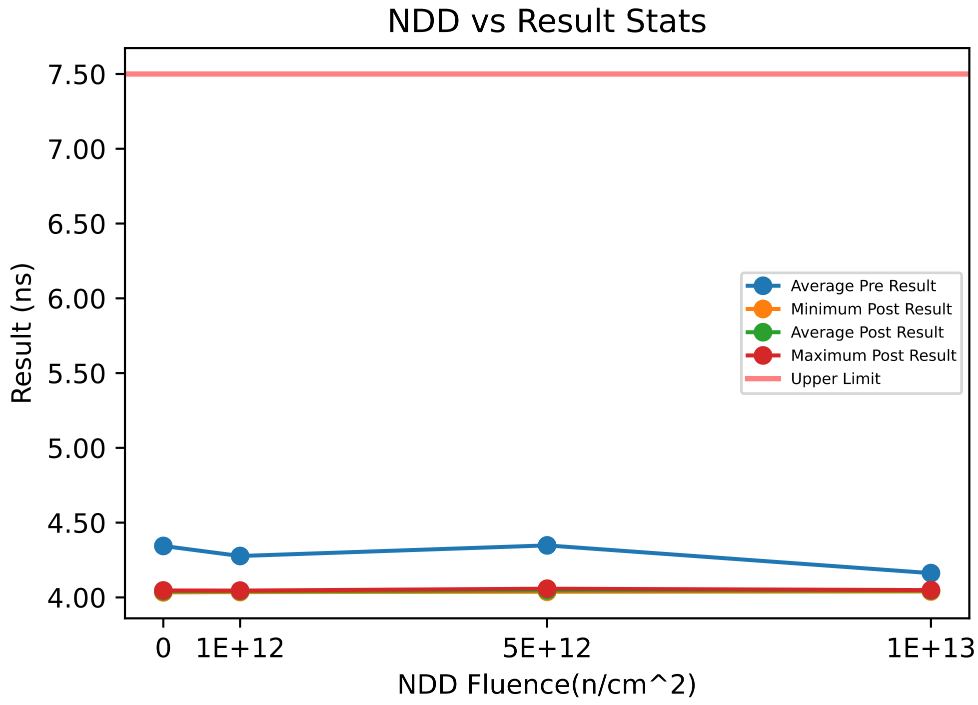
Test Results (Upper Limit = 5.5 (ns))

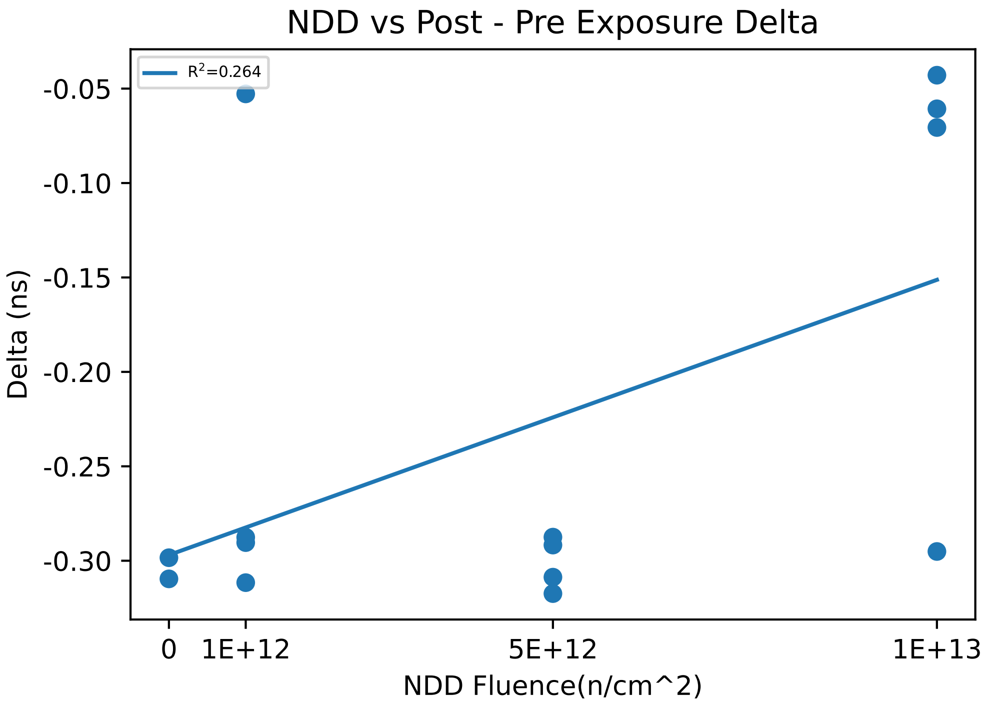
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	3.9047	4.213	0.3083
2	0	Correlation	3.8954	4.2115	0.3161
30	1e+12	NDD unbiased	3.8875	4.2564	0.3689
31	1e+12	NDD unbiased	3.9144	4.2105	0.2961
32	1e+12	NDD unbiased	3.9095	4.2166	0.3071
33	1e+12	NDD unbiased	4.1721	4.2103	0.0382
44	5e+12	NDD unbiased	3.9039	4.2204	0.3165
45	5e+12	NDD unbiased	3.9115	4.213	0.3015
46	5e+12	NDD unbiased	3.9031	4.2091	0.306
47	5e+12	NDD unbiased	3.9126	4.2118	0.2992
50	1e+13	NDD unbiased	4.223	4.2334	0.0104
51	1e+13	NDD unbiased	3.9179	4.2218	0.3039
52	1e+13	NDD unbiased	4.1879	4.2132	0.0253
53	1e+13	NDD unbiased	4.2161	4.2294	0.0133

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.8954	3.9001	3.9047	0.0065761	4.2115	4.2123	4.213	0.0010607	0.3083	0.3122	0.3161	0.0055154
1e+12	3.8875	3.9709	4.1721	0.13466	4.2103	4.2234	4.2564	0.02216	0.0382	0.25257	0.3689	0.14646
5e+12	3.9031	3.9078	3.9126	0.0049675	4.2091	4.2136	4.2204	0.0048335	0.2992	0.3058	0.3165	0.007672
1e+13	3.9179	4.1362	4.223	0.14634	4.2132	4.2245	4.2334	0.0089105	0.0104	0.088225	0.3039	0.14393

Device Test: 116.0 SW_T_HRC(_Rise Time HO VIN_12V)


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

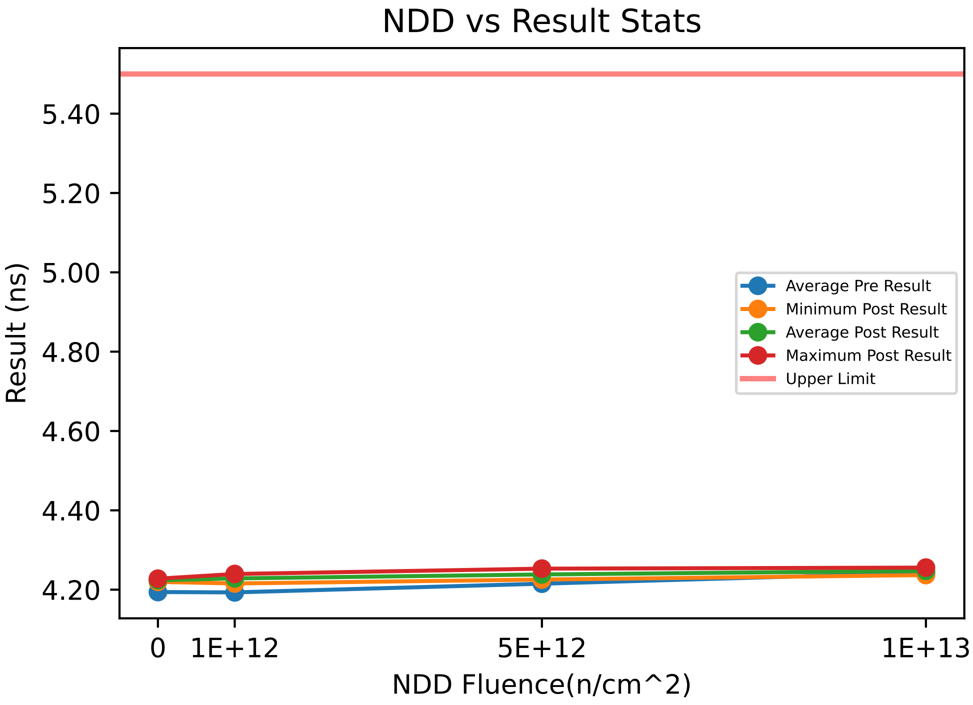
Test Results (Upper Limit = 7.5 (ns))

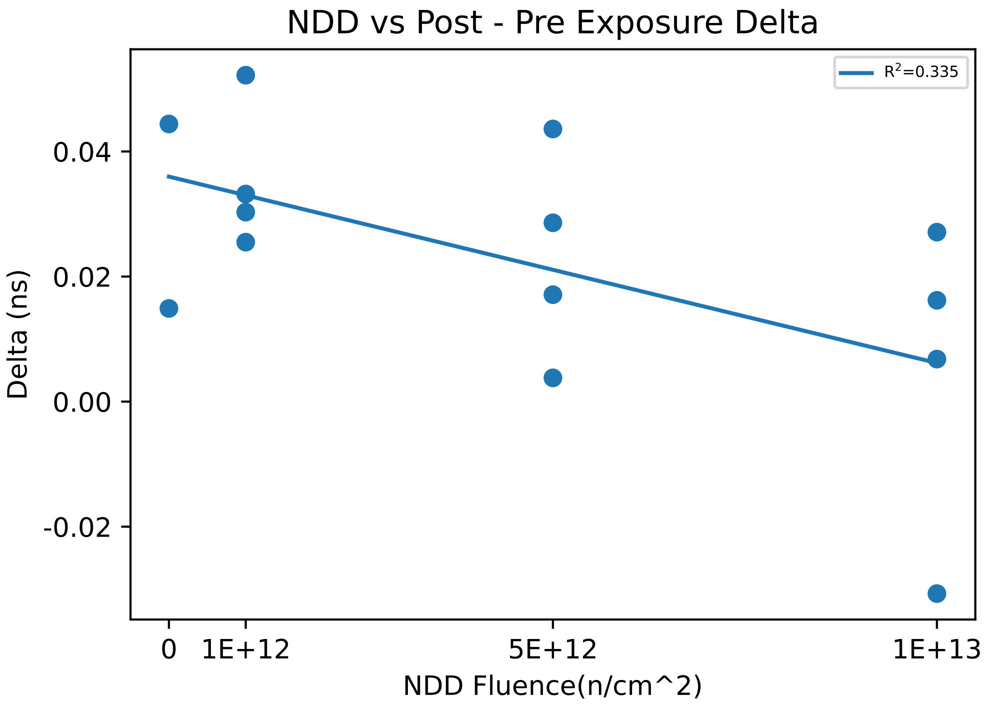
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	4.345	4.0466	-0.2984
2	0	Correlation	4.3431	4.0335	-0.3096
30	1e+12	NDD unbiased	4.3294	4.0418	-0.2876
31	1e+12	NDD unbiased	4.3574	4.0458	-0.3116
32	1e+12	NDD unbiased	4.3325	4.0421	-0.2904
33	1e+12	NDD unbiased	4.0882	4.0354	-0.0528
44	5e+12	NDD unbiased	4.3389	4.0472	-0.2917
45	5e+12	NDD unbiased	4.3607	4.0433	-0.3174
46	5e+12	NDD unbiased	4.3457	4.0582	-0.2875
47	5e+12	NDD unbiased	4.346	4.0373	-0.3087
50	1e+13	NDD unbiased	4.0822	4.0393	-0.0429
51	1e+13	NDD unbiased	4.3392	4.0441	-0.2951
52	1e+13	NDD unbiased	4.1097	4.049	-0.0607
53	1e+13	NDD unbiased	4.1185	4.0479	-0.0706

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.3431	4.344	4.345	0.0013435	4.0335	4.04	4.0466	0.0092631	-0.3096	-0.304	-0.2984	0.0079196
1e+12	4.0882	4.2769	4.3574	0.12641	4.0354	4.0413	4.0458	0.0043185	-0.3116	-0.2356	-0.0528	0.12234
5e+12	4.3389	4.3478	4.3607	0.0091882	4.0373	4.0465	4.0582	0.0087989	-0.3174	-0.30132	-0.2875	0.014102
1e+13	4.0822	4.1624	4.3392	0.11888	4.0393	4.0451	4.049	0.0043851	-0.2951	-0.11732	-0.0429	0.11907

Device Test: 116.1 SW_T_HFC(_Fall Time HO VIN_12V)





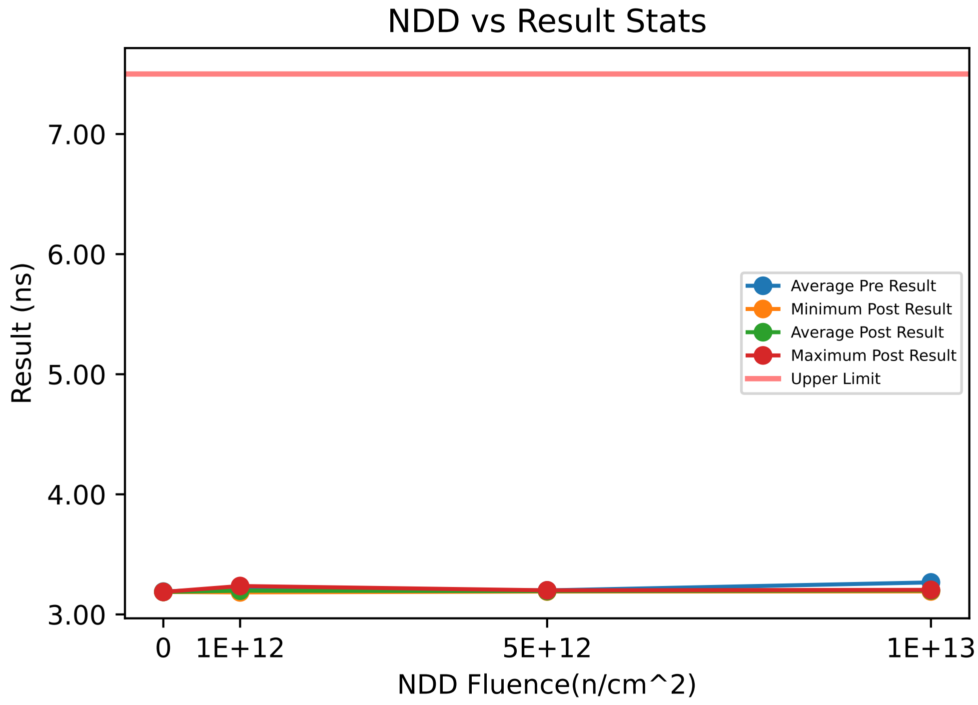
Test Results (Upper Limit = 5.5 (ns))

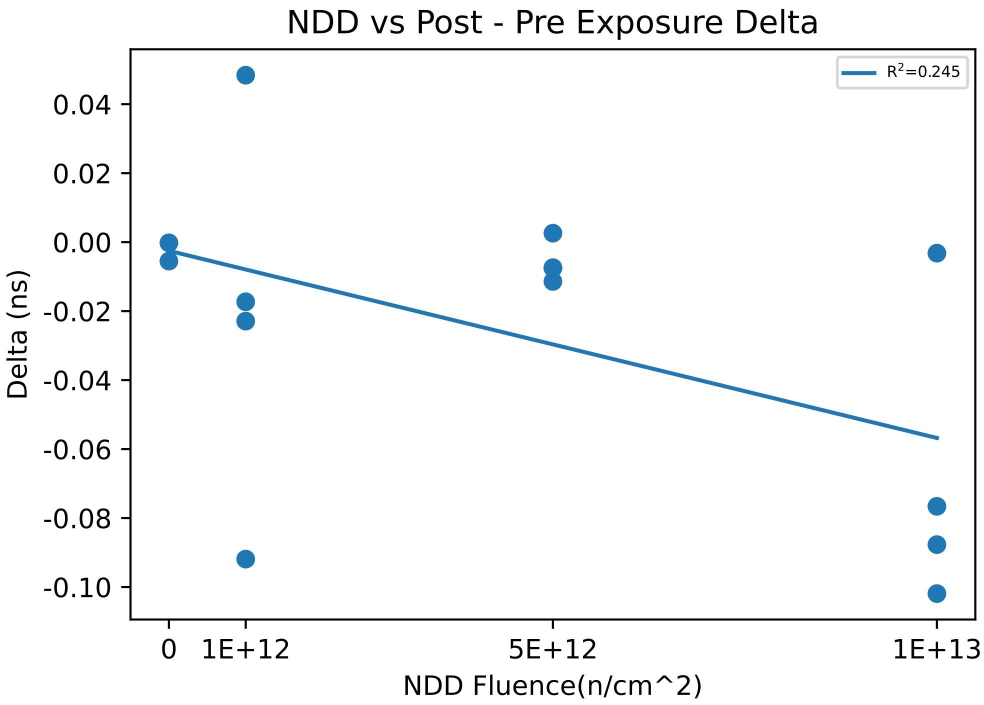
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	4.2128	4.2277	0.0149
2	0	Correlation	4.1753	4.2197	0.0444
30	1e+12	NDD unbiased	4.1873	4.2395	0.0522
31	1e+12	NDD unbiased	4.2076	4.2379	0.0303
32	1e+12	NDD unbiased	4.1824	4.2156	0.0332
33	1e+12	NDD unbiased	4.1952	4.2207	0.0255
44	5e+12	NDD unbiased	4.2005	4.2441	0.0436
45	5e+12	NDD unbiased	4.2217	4.2255	0.0038
46	5e+12	NDD unbiased	4.2244	4.253	0.0286
47	5e+12	NDD unbiased	4.2137	4.2308	0.0171
50	1e+13	NDD unbiased	4.2097	4.2368	0.0271
51	1e+13	NDD unbiased	4.2284	4.2446	0.0162
52	1e+13	NDD unbiased	4.2488	4.2556	0.0068
53	1e+13	NDD unbiased	4.2836	4.2529	-0.0307

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.1753	4.194	4.2128	0.026517	4.2197	4.2237	4.2277	0.0056569	0.0149	0.02965	0.0444	0.02086
1e+12	4.1824	4.1931	4.2076	0.010997	4.2156	4.2284	4.2395	0.012064	0.0255	0.0353	0.0522	0.011706
5e+12	4.2005	4.2151	4.2244	0.010726	4.2255	4.2384	4.253	0.012514	0.0038	0.023275	0.0436	0.01692
1e+13	4.2097	4.2426	4.2836	0.031641	4.2368	4.2475	4.2556	0.008518	-0.0307	0.00485	0.0271	0.02511

Device Test: 116.2 SW_T_LRC(_Rise Time LO VIN_12V)





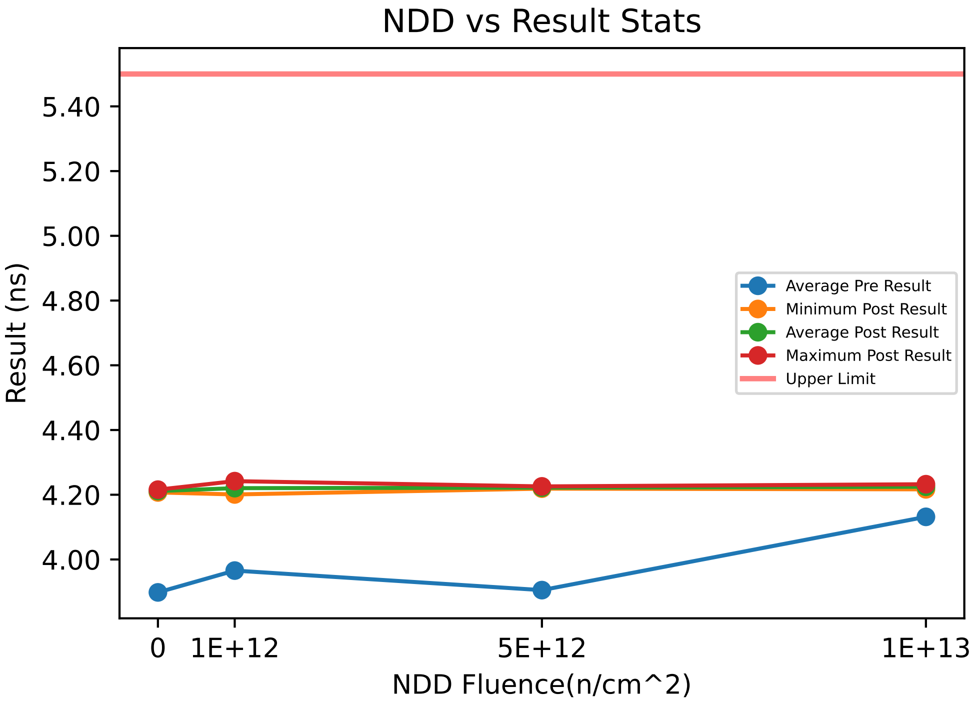
Test Results (Upper Limit = 7.5 (ns))

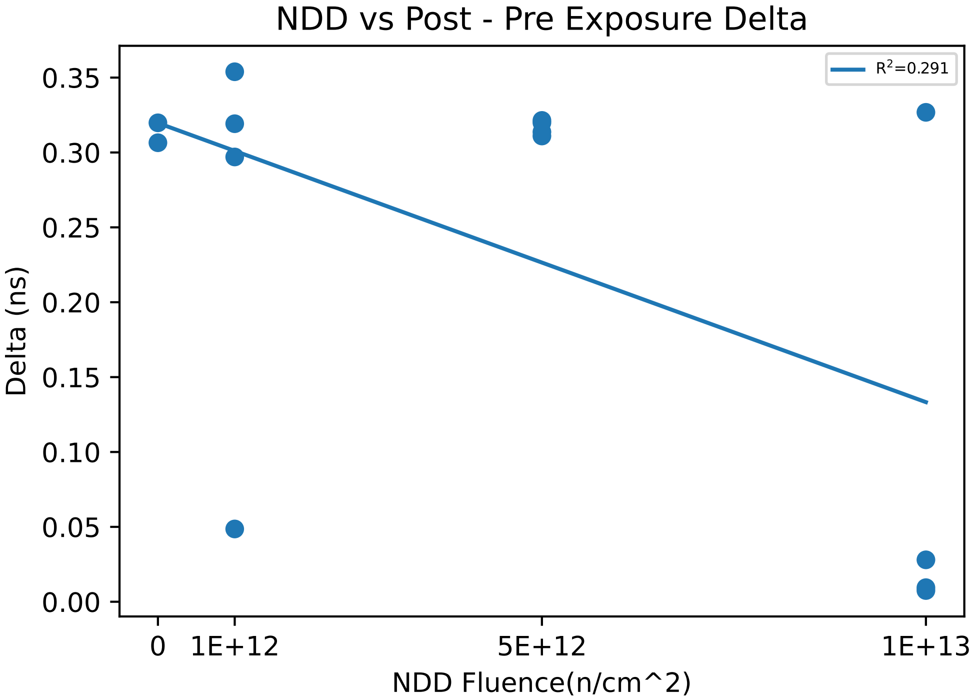
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	3.1873	3.1871	-0.0002
2	0	Correlation	3.1926	3.1871	-0.0055
30	1e+12	NDD unbiased	3.1881	3.2365	0.0484
31	1e+12	NDD unbiased	3.2062	3.1833	-0.0229
32	1e+12	NDD unbiased	3.2032	3.1859	-0.0173
33	1e+12	NDD unbiased	3.2755	3.1836	-0.0919
44	5e+12	NDD unbiased	3.2081	3.2006	-0.0075
45	5e+12	NDD unbiased	3.1911	3.1937	0.0026
46	5e+12	NDD unbiased	3.1986	3.1912	-0.0074
47	5e+12	NDD unbiased	3.2017	3.1903	-0.0114
50	1e+13	NDD unbiased	3.2809	3.2043	-0.0766
51	1e+13	NDD unbiased	3.2	3.1968	-0.0032
52	1e+13	NDD unbiased	3.2789	3.1912	-0.0877
53	1e+13	NDD unbiased	3.3063	3.2044	-0.1019

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.1873	3.19	3.1926	0.0037477	3.1871	3.1871	3.1871	0	-0.0055	-0.00285	-0.0002	0.0037477
1e+12	3.1881	3.2182	3.2755	0.03898	3.1833	3.1973	3.2365	0.026142	-0.0919	-0.020925	0.0484	0.057331
5e+12	3.1911	3.1999	3.2081	0.0070618	3.1903	3.194	3.2006	0.0046608	-0.0114	-0.005925	0.0026	0.0059807
1e+13	3.2	3.2665	3.3063	0.04607	3.1912	3.1992	3.2044	0.0063981	-0.1019	-0.06735	-0.0032	0.044002

Device Test: 116.3 SW_T_LFC(_Fall Time LO VIN_12V)





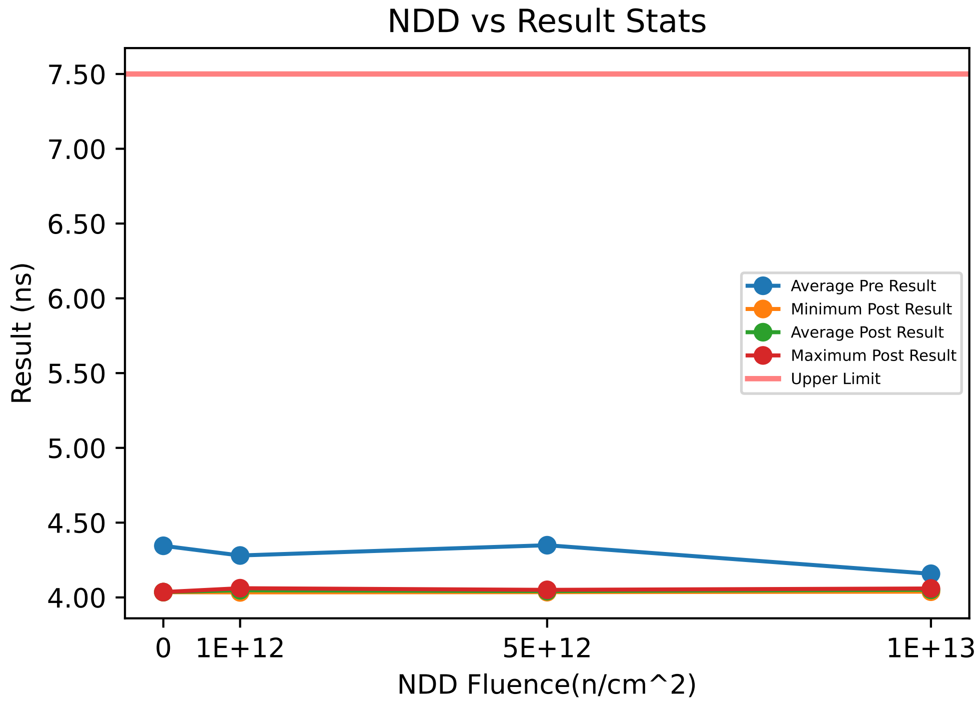
Test Results (Upper Limit = 5.5 (ns))

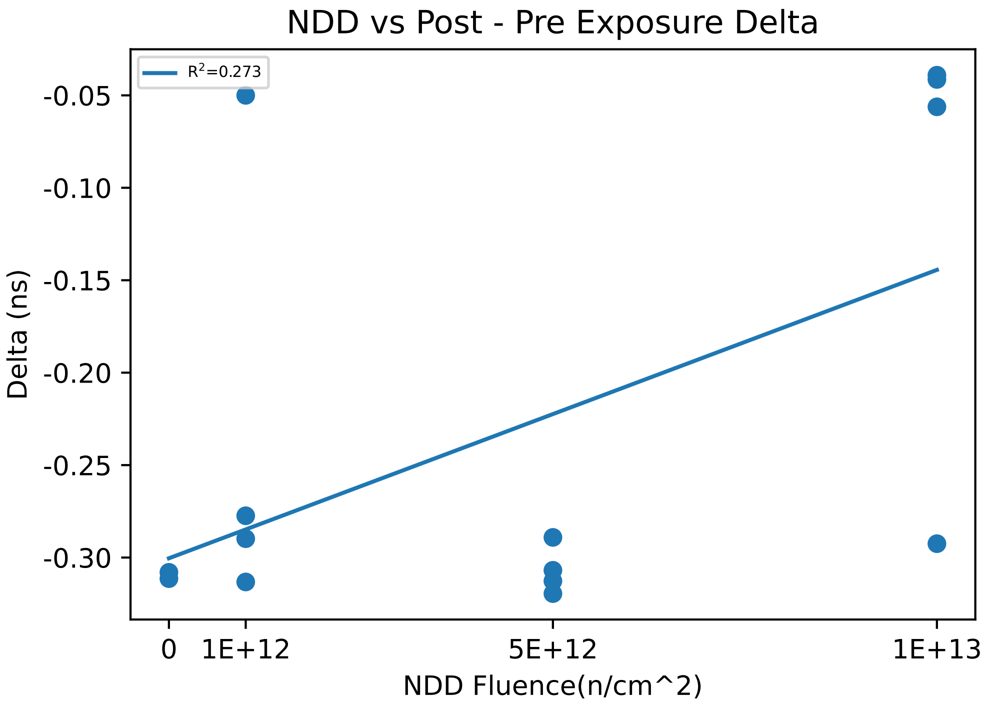
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	3.8959	4.2157	0.3198
2	0	Correlation	3.9006	4.2071	0.3065
30	1e+12	NDD unbiased	3.8881	4.242	0.3539
31	1e+12	NDD unbiased	3.9039	4.2009	0.297
32	1e+12	NDD unbiased	3.8993	4.2185	0.3192
33	1e+12	NDD unbiased	4.1713	4.2199	0.0486
44	5e+12	NDD unbiased	3.9148	4.2258	0.311
45	5e+12	NDD unbiased	3.9051	4.2188	0.3137
46	5e+12	NDD unbiased	3.9017	4.2216	0.3199
47	5e+12	NDD unbiased	3.8996	4.221	0.3214
50	1e+13	NDD unbiased	4.22	4.2294	0.0094
51	1e+13	NDD unbiased	3.9057	4.2325	0.3268
52	1e+13	NDD unbiased	4.1887	4.2167	0.028
53	1e+13	NDD unbiased	4.2124	4.2199	0.0075

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.8959	3.8982	3.9006	0.0033234	4.2071	4.2114	4.2157	0.0060811	0.3065	0.31315	0.3198	0.0094045
1e+12	3.8881	3.9657	4.1713	0.13726	4.2009	4.2203	4.242	0.016839	0.0486	0.25467	0.3539	0.13936
5e+12	3.8996	3.9053	3.9148	0.0067266	4.2188	4.2218	4.2258	0.0029257	0.311	0.3165	0.3214	0.0049551
1e+13	3.9057	4.1317	4.22	0.15126	4.2167	4.2246	4.2325	0.0075266	0.0075	0.092925	0.3268	0.15619

Device Test: 117.0 SW_T_HRC(_Rise Time HO VIN_14V)


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

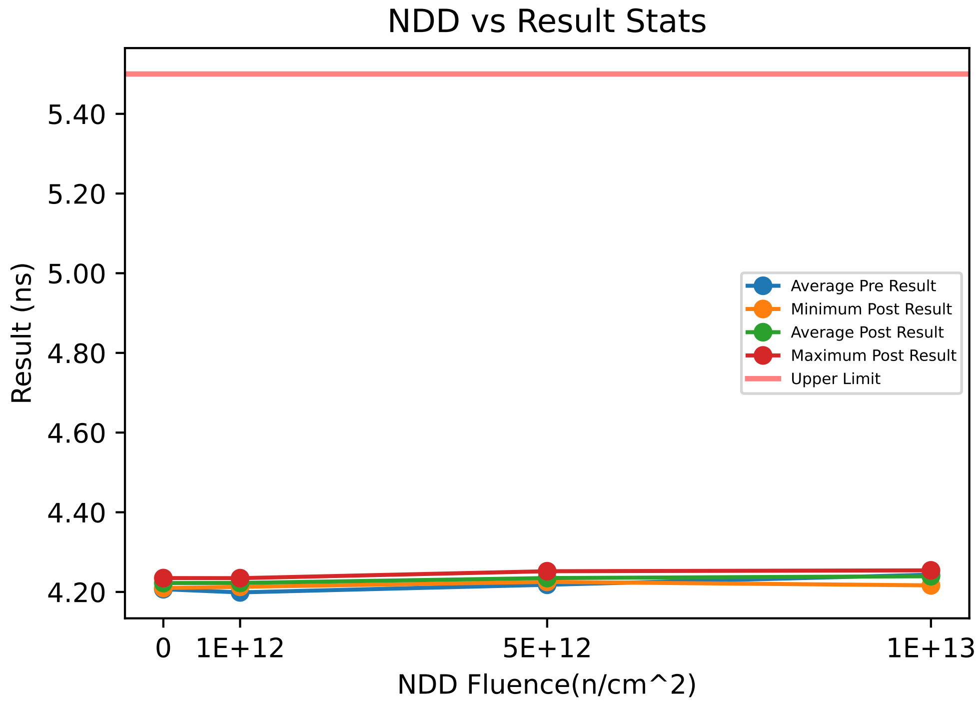
Test Results (Upper Limit = 7.5 (ns))

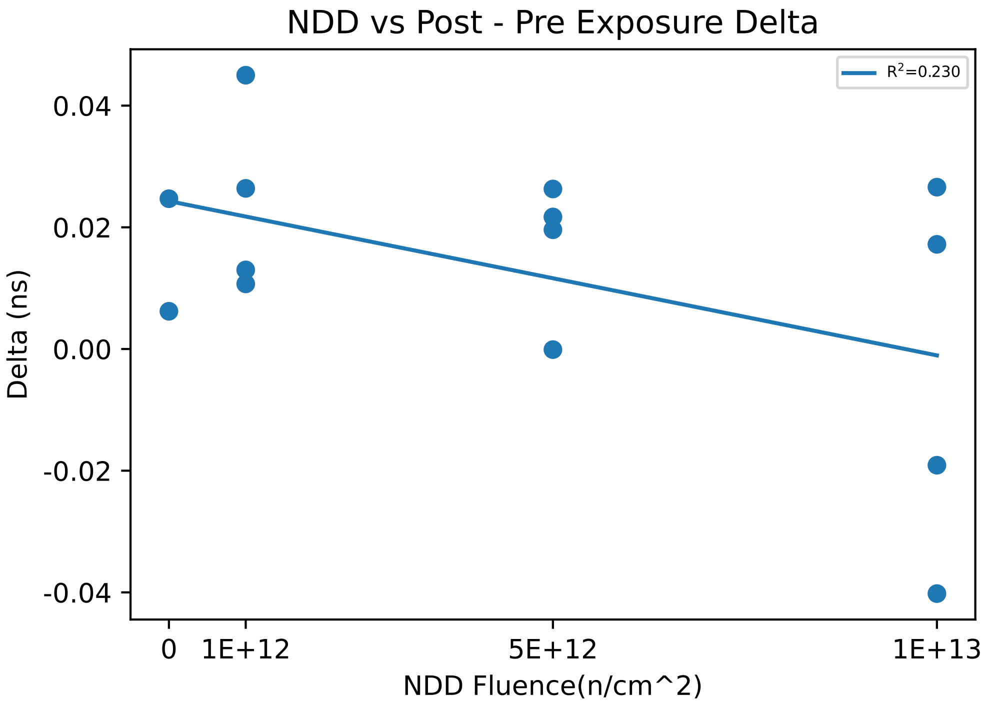
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	4.3431	4.0351	-0.308
2	0	Correlation	4.3473	4.0359	-0.3114
30	1e+12	NDD unbiased	4.339	4.0616	-0.2774
31	1e+12	NDD unbiased	4.347	4.0572	-0.2898
32	1e+12	NDD unbiased	4.3468	4.0336	-0.3132
33	1e+12	NDD unbiased	4.0889	4.0389	-0.05
44	5e+12	NDD unbiased	4.3397	4.0506	-0.2891
45	5e+12	NDD unbiased	4.3547	4.0352	-0.3195
46	5e+12	NDD unbiased	4.3522	4.0453	-0.3069
47	5e+12	NDD unbiased	4.3496	4.0369	-0.3127
50	1e+13	NDD unbiased	4.0919	4.0528	-0.0391
51	1e+13	NDD unbiased	4.3452	4.0527	-0.2925
52	1e+13	NDD unbiased	4.0945	4.0383	-0.0562
53	1e+13	NDD unbiased	4.1012	4.0598	-0.0414

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.3431	4.3452	4.3473	0.0029698	4.0351	4.0355	4.0359	0.00056569	-0.3114	-0.3097	-0.308	0.0024042
1e+12	4.0889	4.2804	4.347	0.12774	4.0336	4.0478	4.0616	0.013658	-0.3132	-0.2326	-0.05	0.12263
5e+12	4.3397	4.3491	4.3547	0.0065719	4.0352	4.042	4.0506	0.0072365	-0.3195	-0.30705	-0.2891	0.013028
1e+13	4.0919	4.1582	4.3452	0.12473	4.0383	4.0509	4.0598	0.0090336	-0.2925	-0.1073	-0.0391	0.1237

Device Test: 117.1 SW_T_HFC(_Fall Time HO VIN_14V)





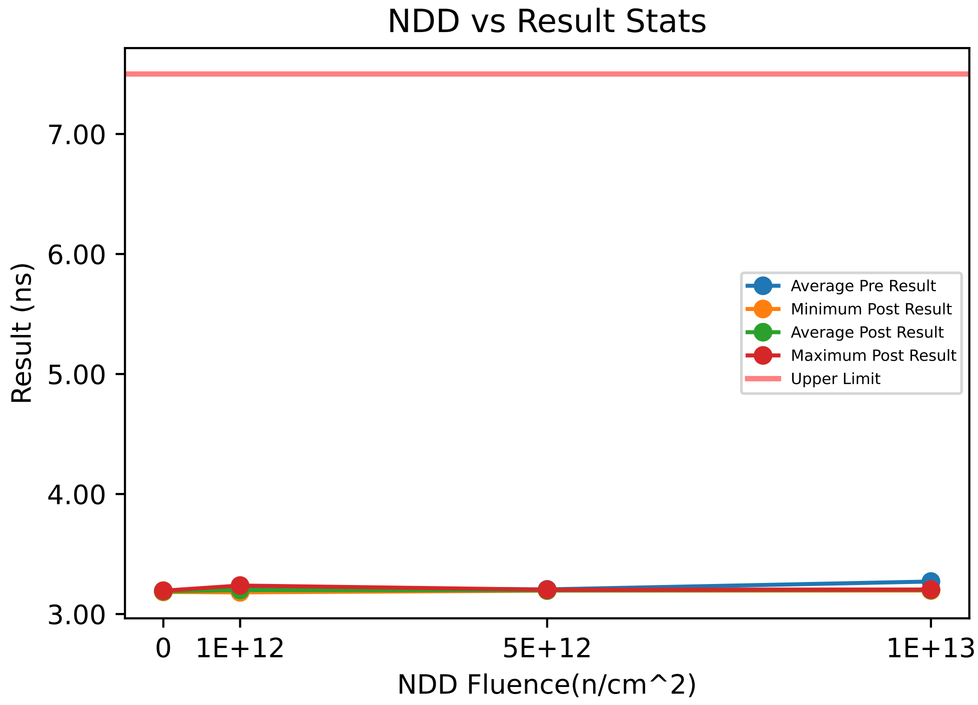
Test Results (Upper Limit = 5.5 (ns))

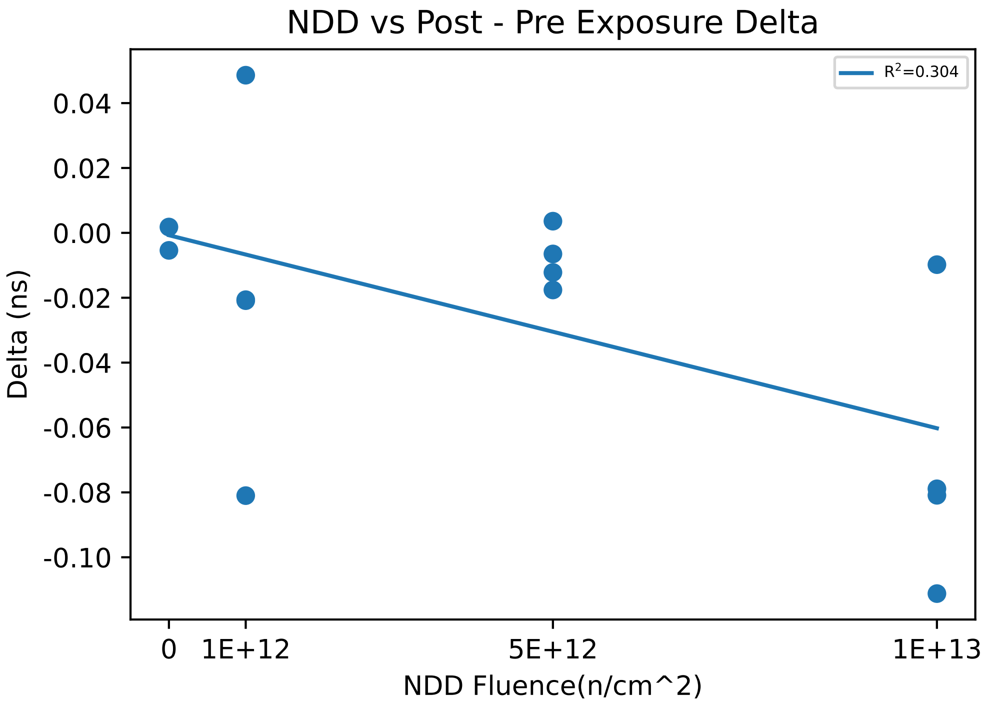
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	4.2101	4.2348	0.0247
2	0	Correlation	4.2036	4.2098	0.0062
30	1e+12	NDD unbiased	4.1896	4.2346	0.045
31	1e+12	NDD unbiased	4.2127	4.2257	0.013
32	1e+12	NDD unbiased	4.1864	4.2128	0.0264
33	1e+12	NDD unbiased	4.2068	4.2175	0.0107
44	5e+12	NDD unbiased	4.212	4.2337	0.0217
45	5e+12	NDD unbiased	4.2253	4.2252	-0.0001
46	5e+12	NDD unbiased	4.2257	4.252	0.0263
47	5e+12	NDD unbiased	4.209	4.2286	0.0196
50	1e+13	NDD unbiased	4.1993	4.2165	0.0172
51	1e+13	NDD unbiased	4.2221	4.2487	0.0266
52	1e+13	NDD unbiased	4.2575	4.2384	-0.0191
53	1e+13	NDD unbiased	4.2944	4.2542	-0.0402

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.2036	4.2068	4.2101	0.0045962	4.2098	4.2223	4.2348	0.017678	0.0062	0.01545	0.0247	0.013081
1e+12	4.1864	4.1989	4.2127	0.012853	4.2128	4.2226	4.2346	0.0095856	0.0107	0.023775	0.045	0.015753
5e+12	4.209	4.218	4.2257	0.008748	4.2252	4.2349	4.252	0.011939	-0.0001	0.016875	0.0263	0.011657
1e+13	4.1993	4.2433	4.2944	0.041626	4.2165	4.2394	4.2542	0.016643	-0.0402	-0.003875	0.0266	0.031221

Device Test: 117.2 SW_T_LRC(_Rise Time LO VIN_14V)





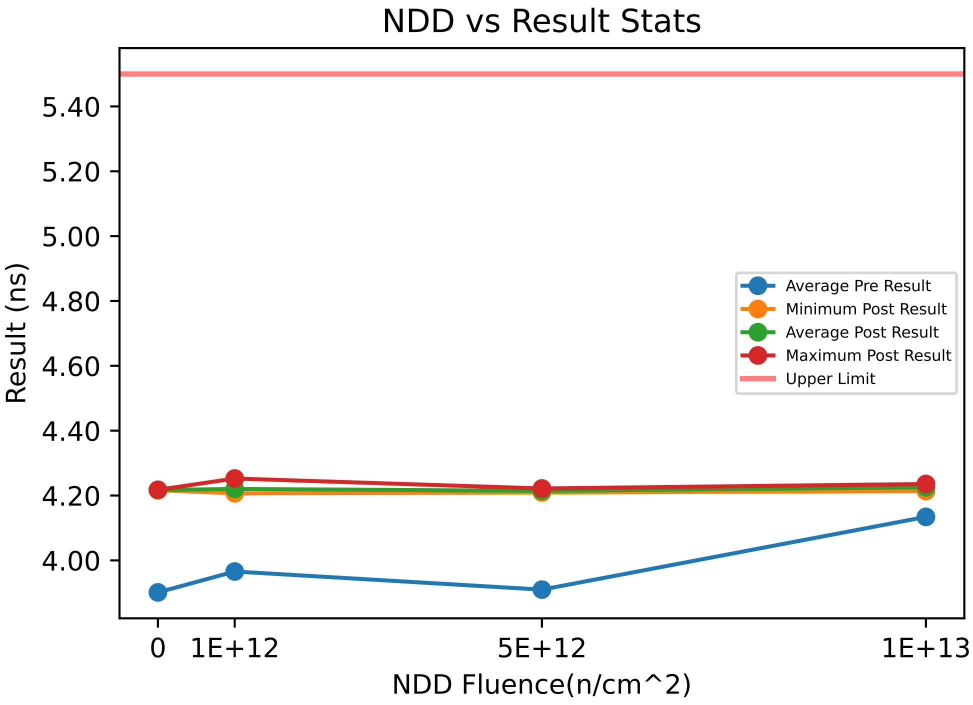
Test Results (Upper Limit = 7.5 (ns))

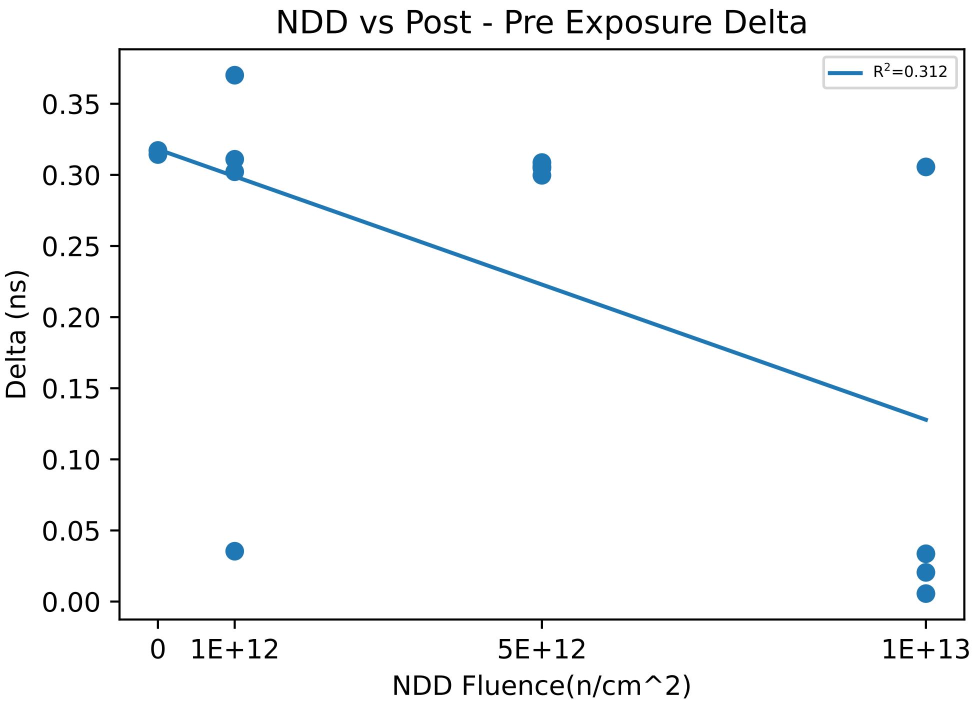
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	3.1928	3.1946	0.0018
2	0	Correlation	3.1896	3.1842	-0.0054
30	1e+12	NDD unbiased	3.189	3.2376	0.0486
31	1e+12	NDD unbiased	3.2013	3.1804	-0.0209
32	1e+12	NDD unbiased	3.2082	3.1876	-0.0206
33	1e+12	NDD unbiased	3.2746	3.1936	-0.081
44	5e+12	NDD unbiased	3.1995	3.2031	0.0036
45	5e+12	NDD unbiased	3.2021	3.1956	-0.0065
46	5e+12	NDD unbiased	3.2126	3.195	-0.0176
47	5e+12	NDD unbiased	3.2075	3.1953	-0.0122
50	1e+13	NDD unbiased	3.2854	3.2045	-0.0809
51	1e+13	NDD unbiased	3.2119	3.2021	-0.0098
52	1e+13	NDD unbiased	3.2801	3.2012	-0.0789
53	1e+13	NDD unbiased	3.3068	3.1956	-0.1112

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.1896	3.1912	3.1928	0.0022627	3.1842	3.1894	3.1946	0.0073539	-0.0054	-0.0018	0.0018	0.0050912
1e+12	3.189	3.2183	3.2746	0.03838	3.1804	3.1998	3.2376	0.025771	-0.081	-0.018475	0.0486	0.052974
5e+12	3.1995	3.2054	3.2126	0.0058295	3.195	3.1972	3.2031	0.0039077	-0.0176	-0.008175	0.0036	0.0090644
1e+13	3.2119	3.271	3.3068	0.041088	3.1956	3.2008	3.2045	0.003767	-0.1112	-0.0702	-0.0098	0.042893

Device Test: 117.3 SW_T_LFC(_Fall Time LO VIN_14V)





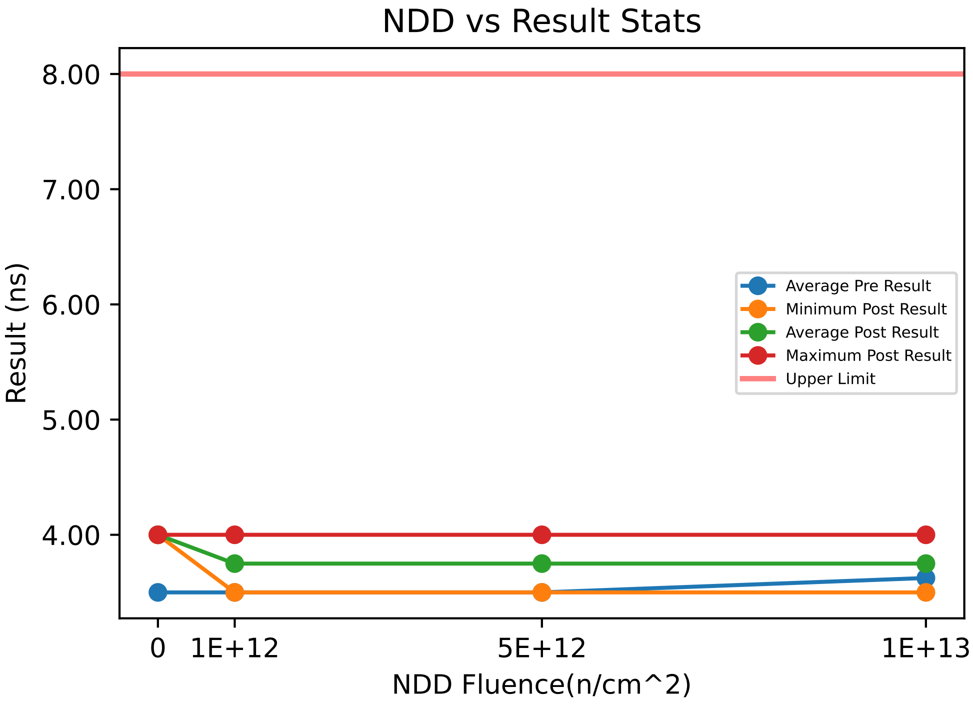
Test Results (Upper Limit = 5.5 (ns))

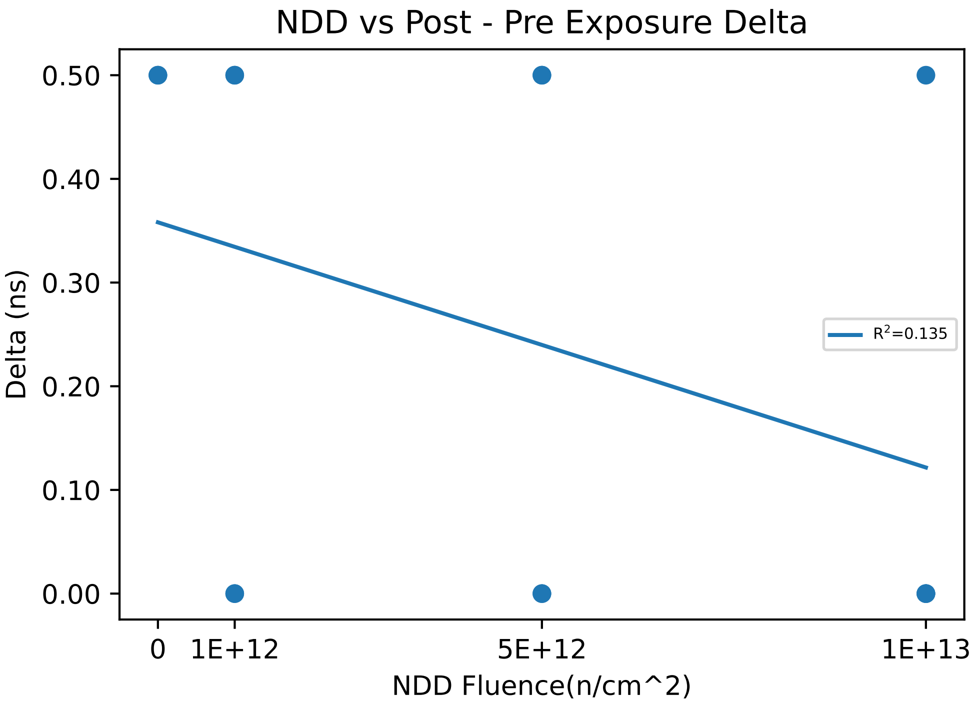
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	3.9004	4.2176	0.3172
2	0	Correlation	3.9021	4.2164	0.3143
30	1e+12	NDD unbiased	3.8824	4.2525	0.3701
31	1e+12	NDD unbiased	3.9047	4.2069	0.3022
32	1e+12	NDD unbiased	3.8997	4.2107	0.311
33	1e+12	NDD unbiased	4.1759	4.2113	0.0354
44	5e+12	NDD unbiased	3.9131	4.2218	0.3087
45	5e+12	NDD unbiased	3.9095	4.2092	0.2997
46	5e+12	NDD unbiased	3.9118	4.2165	0.3047
47	5e+12	NDD unbiased	3.9047	4.2107	0.306
50	1e+13	NDD unbiased	4.23	4.2356	0.0056
51	1e+13	NDD unbiased	3.9166	4.2222	0.3056
52	1e+13	NDD unbiased	4.1802	4.2138	0.0336
53	1e+13	NDD unbiased	4.2096	4.2301	0.0205

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.9004	3.9013	3.9021	0.0012021	4.2164	4.217	4.2176	0.00084853	0.3143	0.31575	0.3172	0.0020506
1e+12	3.8824	3.9657	4.1759	0.14048	4.2069	4.2203	4.2525	0.021522	0.0354	0.25467	0.3701	0.14926
5e+12	3.9047	3.9098	3.9131	0.0036963	4.2092	4.2146	4.2218	0.005768	0.2997	0.30478	0.3087	0.0037713
1e+13	3.9166	4.1341	4.23	0.14643	4.2138	4.2254	4.2356	0.0095031	0.0056	0.091325	0.3056	0.14331

Device Test: 120.0 SW_T_PW_MIN(_Min Input PW Static HS Turn On VIN_10V)





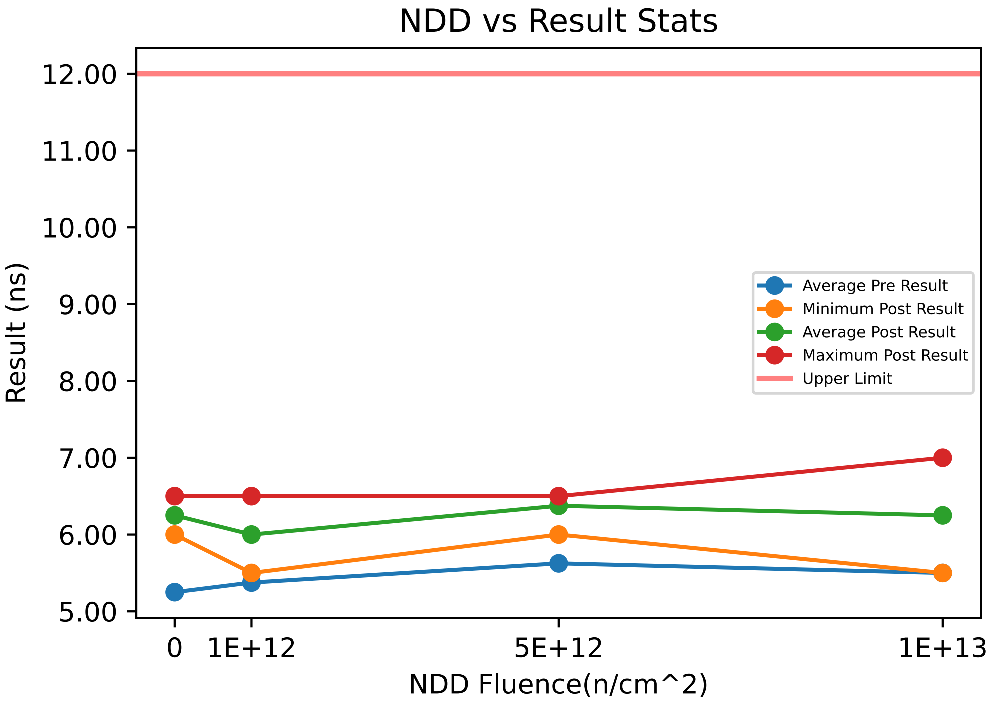
Test Results (Upper Limit = 8.0 (ns))

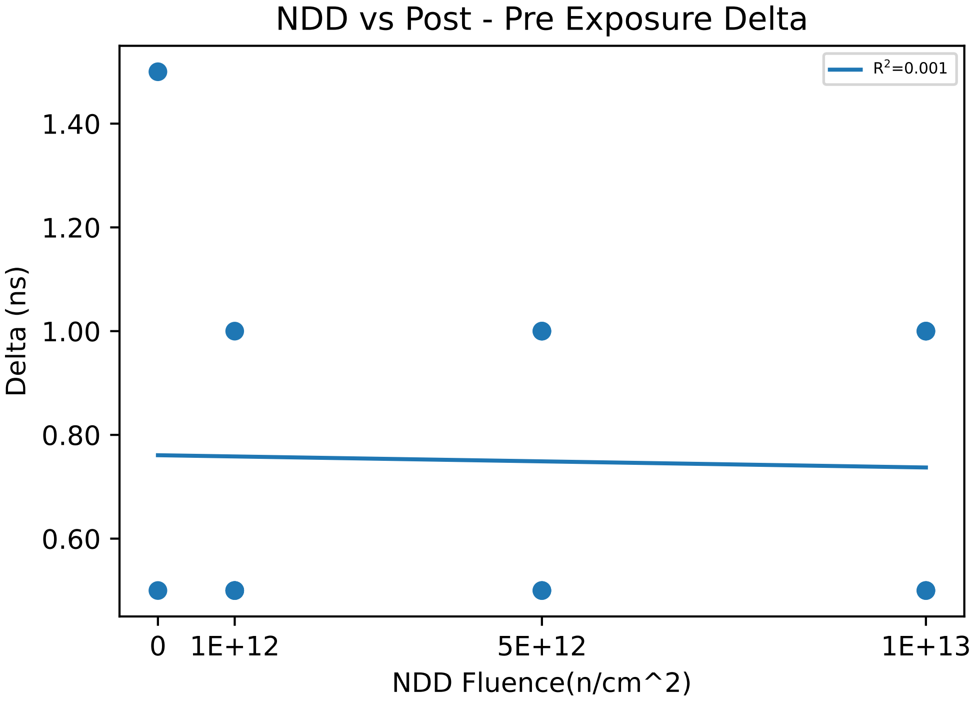
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	3.5	4	0.5
2	0	Correlation	3.5	4	0.5
30	1e+12	NDD unbiased	3.5	3.5	0
31	1e+12	NDD unbiased	3.5	4	0.5
32	1e+12	NDD unbiased	3.5	4	0.5
33	1e+12	NDD unbiased	3.5	3.5	0
44	5e+12	NDD unbiased	3.5	3.5	0
45	5e+12	NDD unbiased	3.5	4	0.5
46	5e+12	NDD unbiased	3.5	3.5	0
47	5e+12	NDD unbiased	3.5	4	0.5
50	1e+13	NDD unbiased	4	4	0
51	1e+13	NDD unbiased	3.5	3.5	0
52	1e+13	NDD unbiased	3.5	4	0.5
53	1e+13	NDD unbiased	3.5	3.5	0

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.5	3.5	3.5	0	4	4	4	0	0.5	0.5	0.5	0
1e+12	3.5	3.5	3.5	0	3.5	3.75	4	0.28868	0	0.25	0.5	0.28868
5e+12	3.5	3.5	3.5	0	3.5	3.75	4	0.28868	0	0.25	0.5	0.28868
1e+13	3.5	3.625	4	0.25	3.5	3.75	4	0.28868	0	0.125	0.5	0.25

Device Test: 120.1 SW_T_PW_MIN_OFF(_Min Input PW Static HS Turn Off VIN_10V)





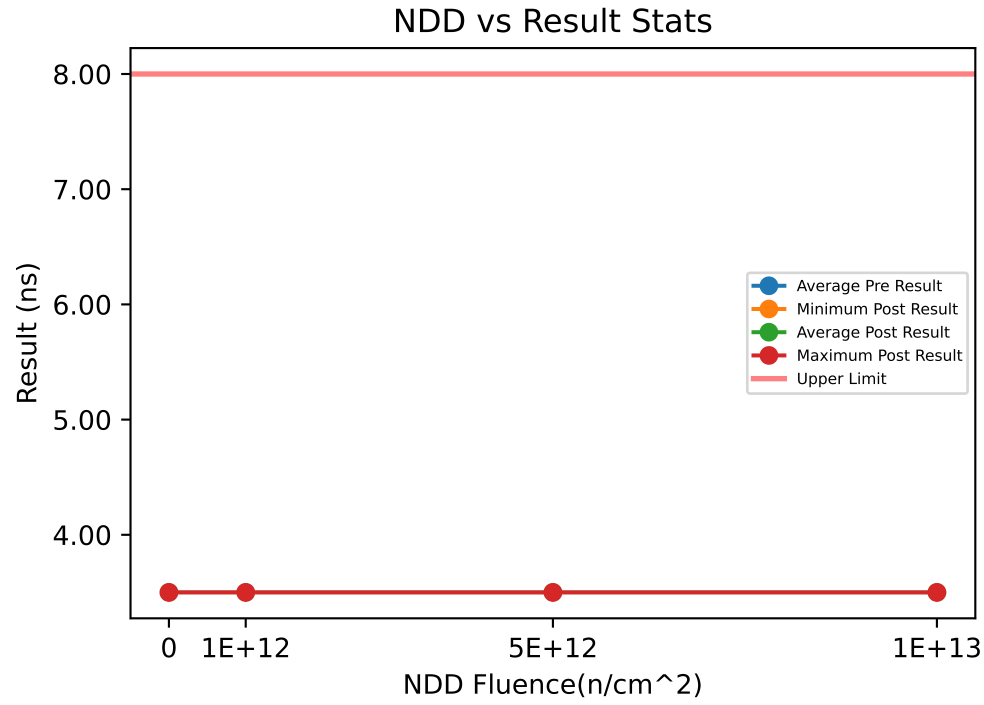
Test Results (Upper Limit = 12.0 (ns))

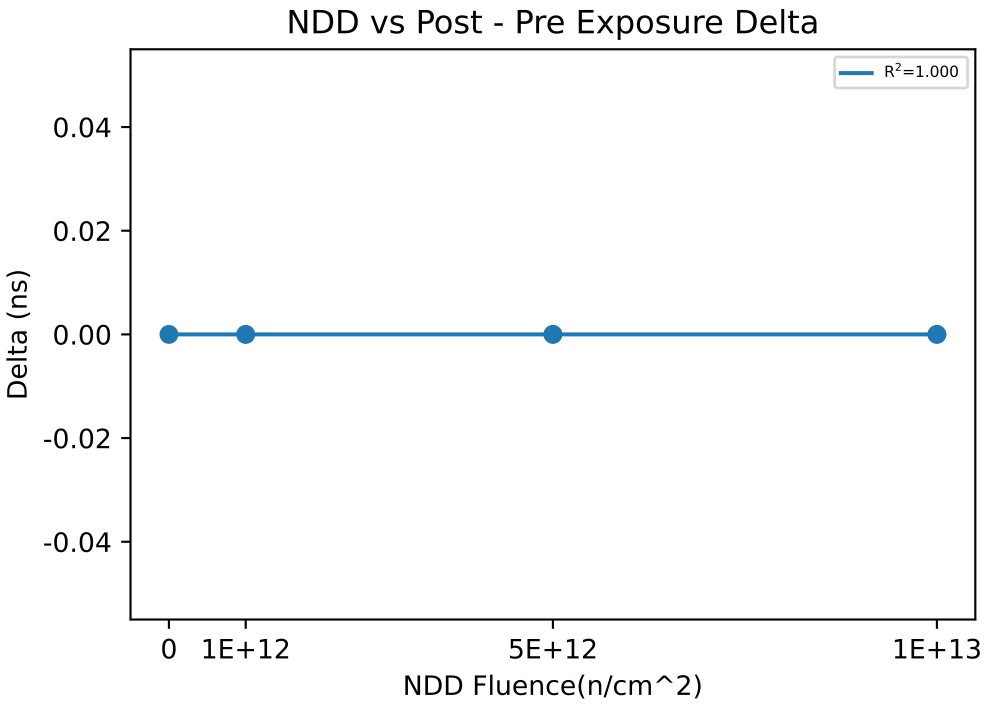
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	5.5	6	0.5
2	0	Correlation	5	6.5	1.5
30	1e+12	NDD unbiased	5.5	6	0.5
31	1e+12	NDD unbiased	5	6	1
32	1e+12	NDD unbiased	6	6.5	0.5
33	1e+12	NDD unbiased	5	5.5	0.5
44	5e+12	NDD unbiased	5	6	1
45	5e+12	NDD unbiased	6	6.5	0.5
46	5e+12	NDD unbiased	5.5	6.5	1
47	5e+12	NDD unbiased	6	6.5	0.5
50	1e+13	NDD unbiased	6	7	1
51	1e+13	NDD unbiased	5.5	6	0.5
52	1e+13	NDD unbiased	5.5	6.5	1
53	1e+13	NDD unbiased	5	5.5	0.5

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5	5.25	5.5	0.35355	6	6.25	6.5	0.35355	0.5	1	1.5	0.70711
1e+12	5	5.375	6	0.47871	5.5	6	6.5	0.40825	0.5	0.625	1	0.25
5e+12	5	5.625	6	0.47871	6	6.375	6.5	0.25	0.5	0.75	1	0.28868
1e+13	5	5.5	6	0.40825	5.5	6.25	7	0.6455	0.5	0.75	1	0.28868

Device Test: 120.2 SW_T_PW_MIN(_Min Input PW Static LS Turn On VIN_10V)


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

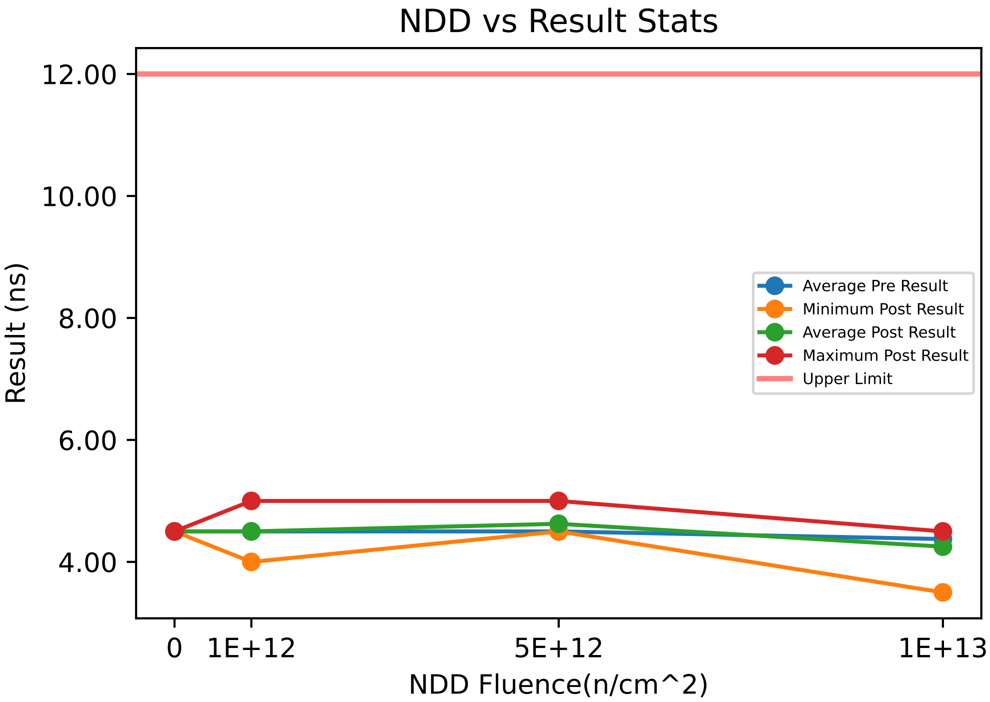
Test Results (Upper Limit = 8.0 (ns))

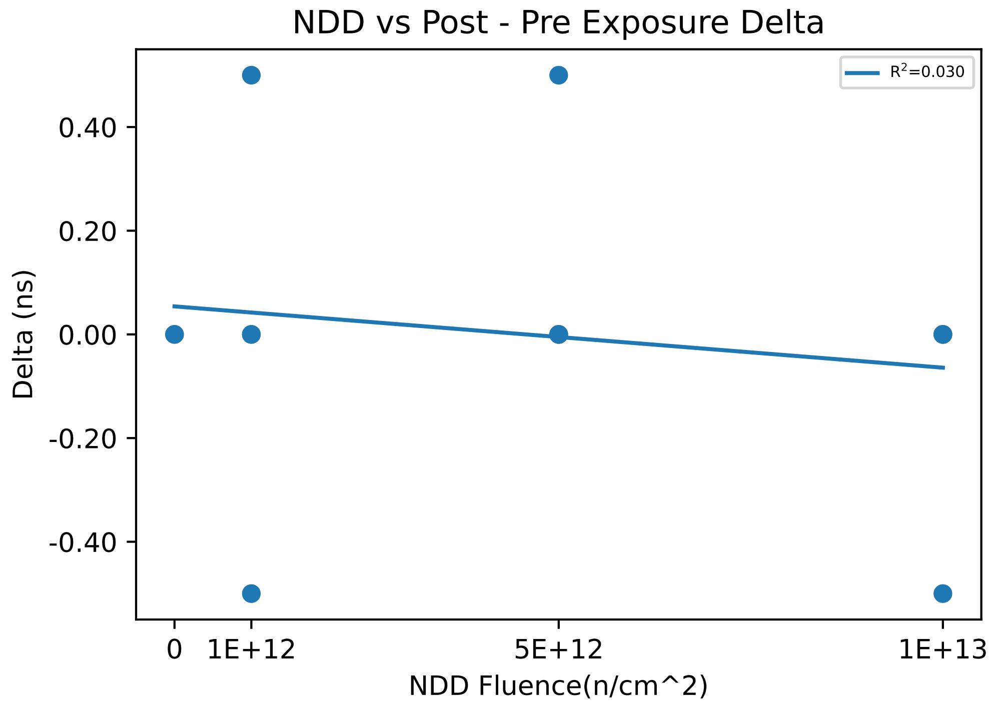
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	3.5	3.5	0
2	0	Correlation	3.5	3.5	0
30	1e+12	NDD unbiased	3.5	3.5	0
31	1e+12	NDD unbiased	3.5	3.5	0
32	1e+12	NDD unbiased	3.5	3.5	0
33	1e+12	NDD unbiased	3.5	3.5	0
44	5e+12	NDD unbiased	3.5	3.5	0
45	5e+12	NDD unbiased	3.5	3.5	0
46	5e+12	NDD unbiased	3.5	3.5	0
47	5e+12	NDD unbiased	3.5	3.5	0
50	1e+13	NDD unbiased	3.5	3.5	0
51	1e+13	NDD unbiased	3.5	3.5	0
52	1e+13	NDD unbiased	3.5	3.5	0
53	1e+13	NDD unbiased	3.5	3.5	0

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.5	3.5	3.5	0	3.5	3.5	3.5	0	0	0	0	0
1e+12	3.5	3.5	3.5	0	3.5	3.5	3.5	0	0	0	0	0
5e+12	3.5	3.5	3.5	0	3.5	3.5	3.5	0	0	0	0	0
1e+13	3.5	3.5	3.5	0	3.5	3.5	3.5	0	0	0	0	0

Device Test: 120.3 SW_T_PW_MIN_OFF(_Min Input PW Static LS Turn Off VIN_10V)





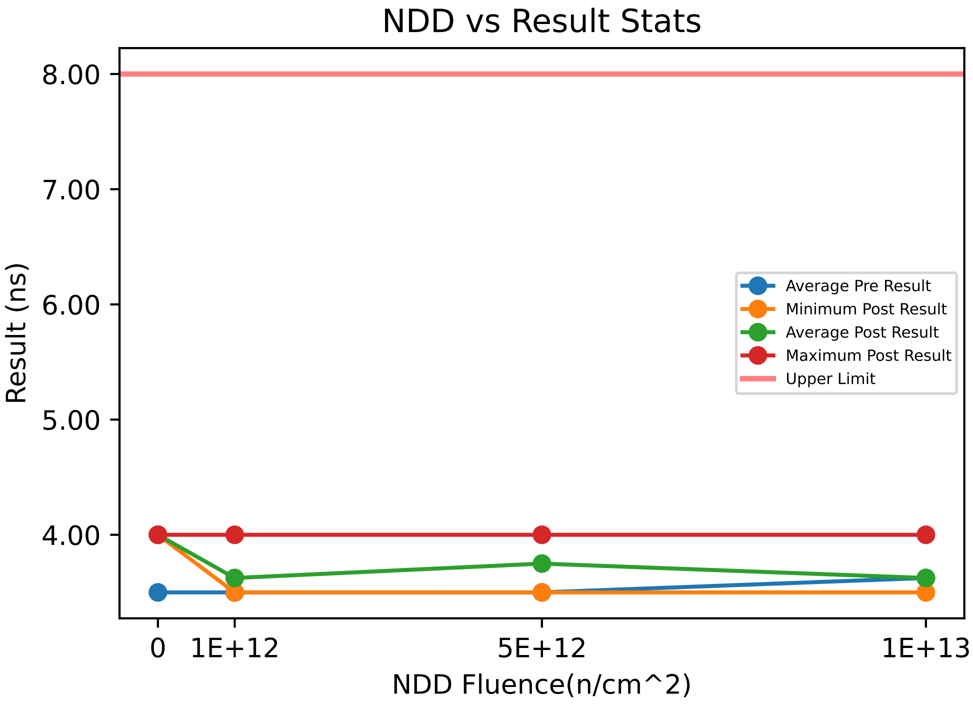
Test Results (Upper Limit = 12.0 (ns))

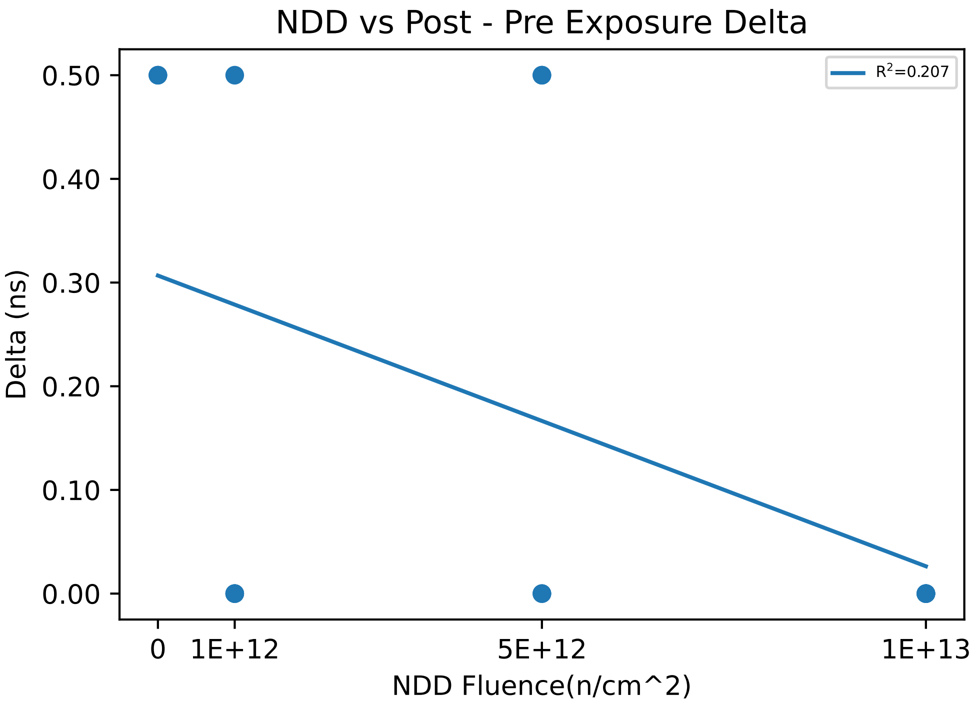
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	4.5	4.5	0
2	0	Correlation	4.5	4.5	0
30	1e+12	NDD unbiased	4	4.5	0.5
31	1e+12	NDD unbiased	4.5	4	-0.5
32	1e+12	NDD unbiased	4.5	4.5	0
33	1e+12	NDD unbiased	5	5	0
44	5e+12	NDD unbiased	5	5	0
45	5e+12	NDD unbiased	4	4.5	0.5
46	5e+12	NDD unbiased	4.5	4.5	0
47	5e+12	NDD unbiased	4.5	4.5	0
50	1e+13	NDD unbiased	5	4.5	-0.5
51	1e+13	NDD unbiased	3.5	3.5	0
52	1e+13	NDD unbiased	4.5	4.5	0
53	1e+13	NDD unbiased	4.5	4.5	0

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.5	4.5	4.5	0	4.5	4.5	4.5	0	0	0	0	0
1e+12	4	4.5	5	0.40825	4	4.5	5	0.40825	-0.5	0	0.5	0.40825
5e+12	4	4.5	5	0.40825	4.5	4.625	5	0.25	0	0.125	0.5	0.25
1e+13	3.5	4.375	5	0.62915	3.5	4.25	4.5	0.5	-0.5	-0.125	0	0.25

Device Test: 120.4 SW_T_PW_MIN(_Min Input PW Static HS Turn On SW=100V VIN_10V)





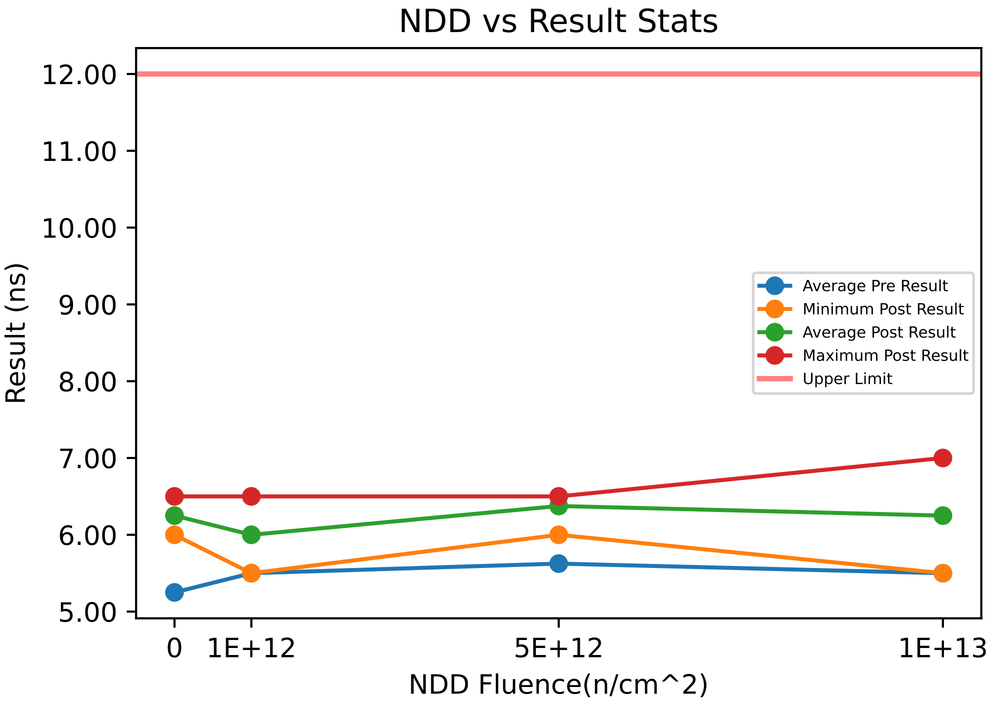
Test Results (Upper Limit = 8.0 (ns))

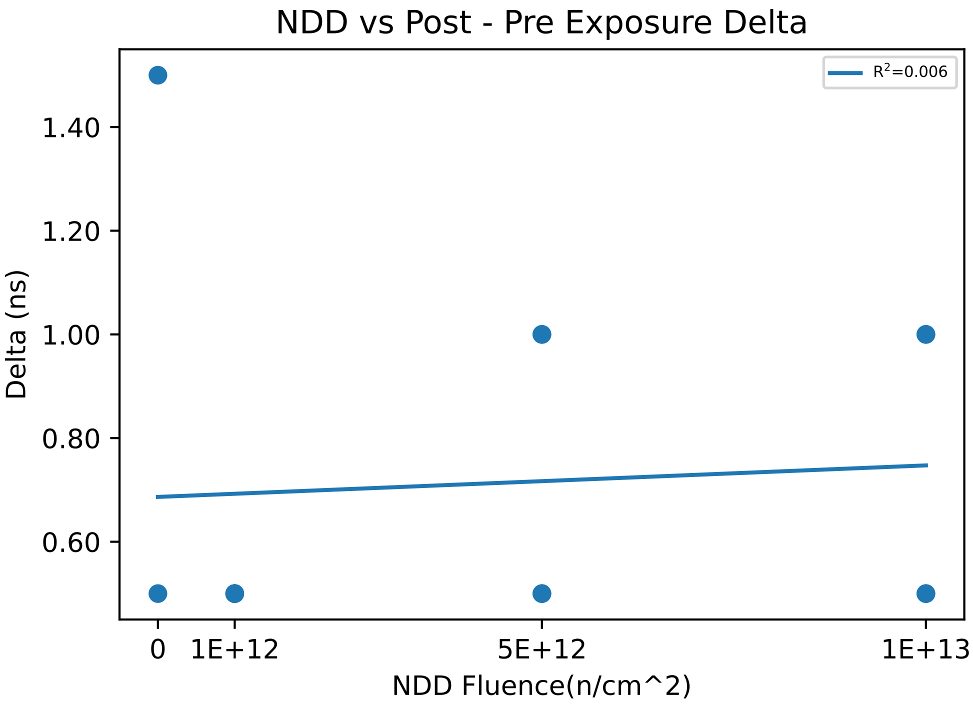
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	3.5	4	0.5
2	0	Correlation	3.5	4	0.5
30	1e+12	NDD unbiased	3.5	3.5	0
31	1e+12	NDD unbiased	3.5	4	0.5
32	1e+12	NDD unbiased	3.5	3.5	0
33	1e+12	NDD unbiased	3.5	3.5	0
44	5e+12	NDD unbiased	3.5	3.5	0
45	5e+12	NDD unbiased	3.5	4	0.5
46	5e+12	NDD unbiased	3.5	3.5	0
47	5e+12	NDD unbiased	3.5	4	0.5
50	1e+13	NDD unbiased	4	4	0
51	1e+13	NDD unbiased	3.5	3.5	0
52	1e+13	NDD unbiased	3.5	3.5	0
53	1e+13	NDD unbiased	3.5	3.5	0

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.5	3.5	3.5	0	4	4	4	0	0.5	0.5	0.5	0
1e+12	3.5	3.5	3.5	0	3.5	3.625	4	0.25	0	0.125	0.5	0.25
5e+12	3.5	3.5	3.5	0	3.5	3.75	4	0.28868	0	0.25	0.5	0.28868
1e+13	3.5	3.625	4	0.25	3.5	3.625	4	0.25	0	0	0	0

Device Test: 120.5 SW_T_PW_MIN_OFF(_Min Input PW Static HS Turn Off SW=100V VIN_10V)


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

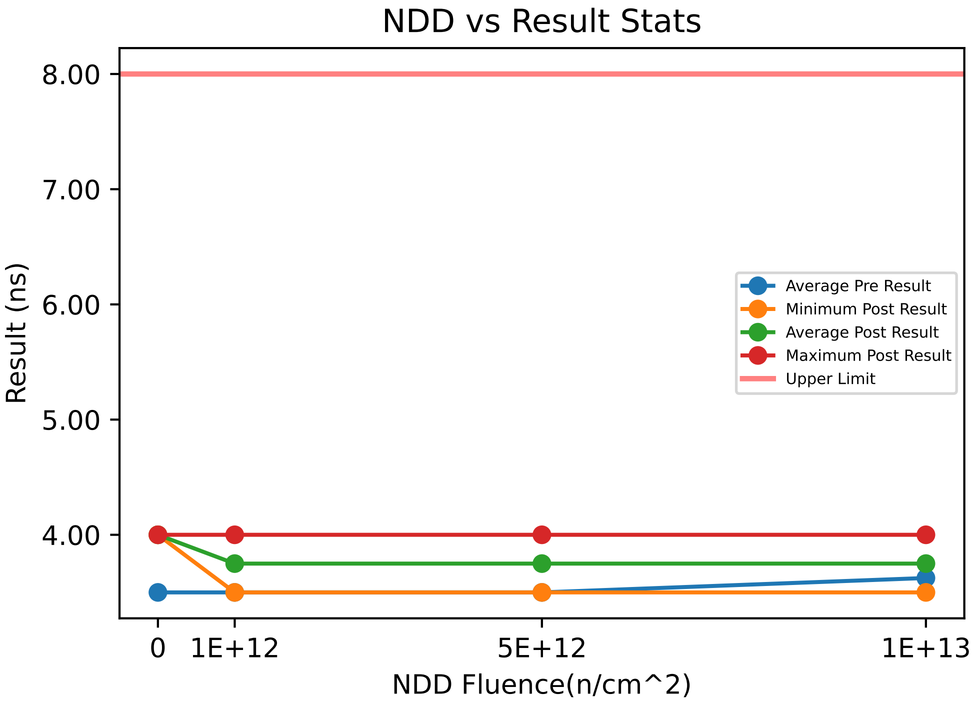
Test Results (Upper Limit = 12.0 (ns))

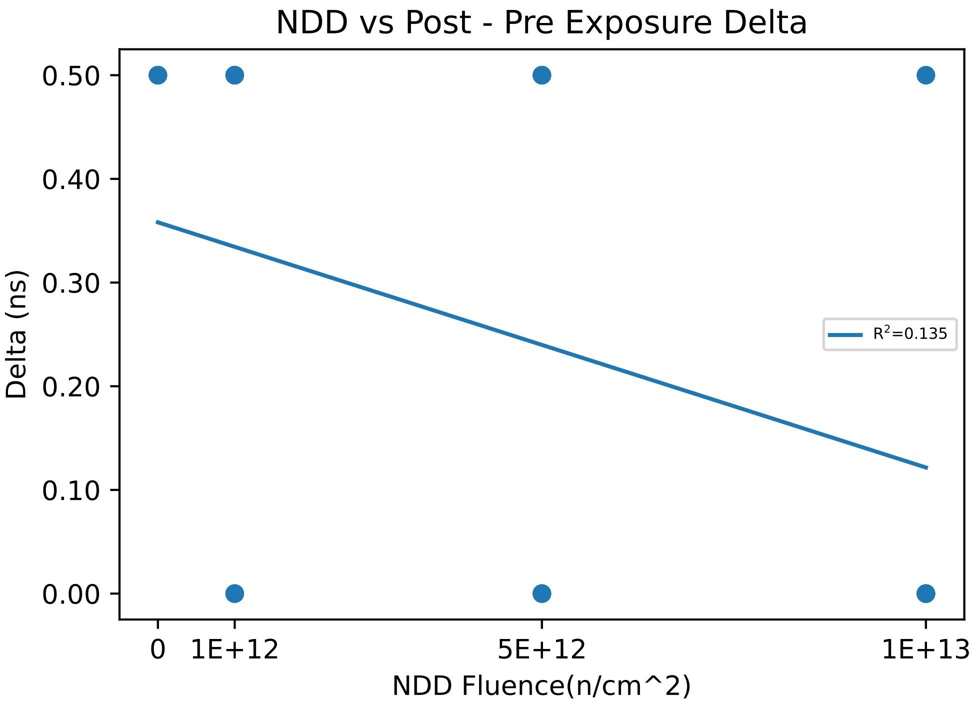
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	5.5	6	0.5
2	0	Correlation	5	6.5	1.5
30	1e+12	NDD unbiased	5.5	6	0.5
31	1e+12	NDD unbiased	5.5	6	0.5
32	1e+12	NDD unbiased	6	6.5	0.5
33	1e+12	NDD unbiased	5	5.5	0.5
44	5e+12	NDD unbiased	5	6	1
45	5e+12	NDD unbiased	6	6.5	0.5
46	5e+12	NDD unbiased	5.5	6.5	1
47	5e+12	NDD unbiased	6	6.5	0.5
50	1e+13	NDD unbiased	6	7	1
51	1e+13	NDD unbiased	5.5	6	0.5
52	1e+13	NDD unbiased	5.5	6.5	1
53	1e+13	NDD unbiased	5	5.5	0.5

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5	5.25	5.5	0.35355	6	6.25	6.5	0.35355	0.5	1	1.5	0.70711
1e+12	5	5.5	6	0.40825	5.5	6	6.5	0.40825	0.5	0.5	0.5	0
5e+12	5	5.625	6	0.47871	6	6.375	6.5	0.25	0.5	0.75	1	0.28868
1e+13	5	5.5	6	0.40825	5.5	6.25	7	0.6455	0.5	0.75	1	0.28868

Device Test: 121.0 SW_T_PW_MIN(_Min Input PW Static HS Turn On VIN_12V)





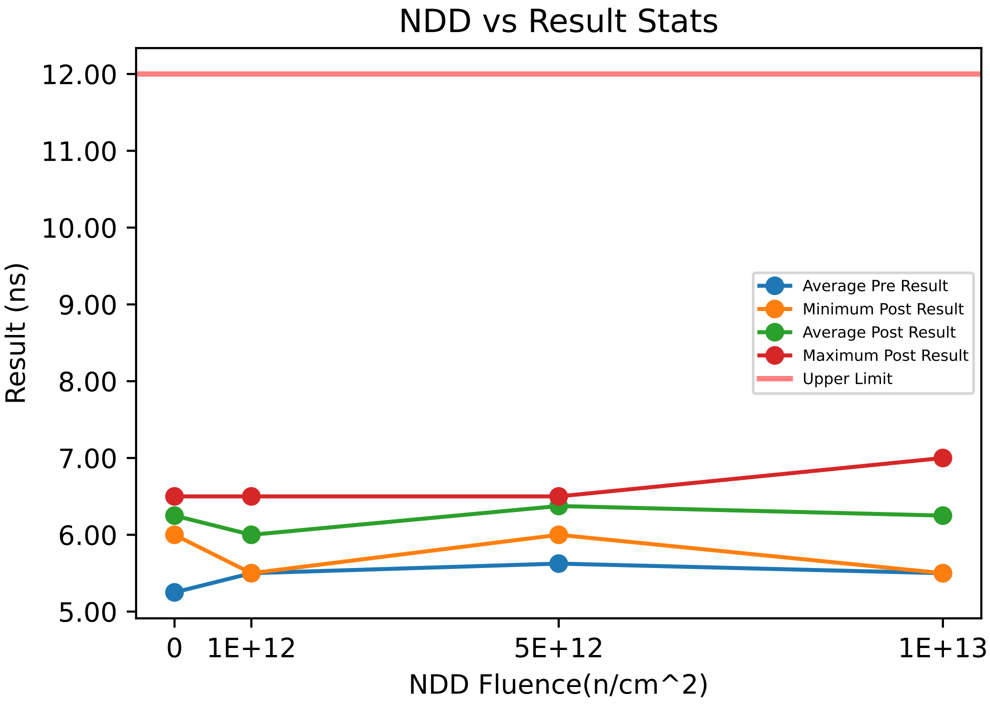
Test Results (Upper Limit = 8.0 (ns))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	3.5	4	0.5
2	0	Correlation	3.5	4	0.5
30	1e+12	NDD unbiased	3.5	3.5	0
31	1e+12	NDD unbiased	3.5	4	0.5
32	1e+12	NDD unbiased	3.5	4	0.5
33	1e+12	NDD unbiased	3.5	3.5	0
44	5e+12	NDD unbiased	3.5	3.5	0
45	5e+12	NDD unbiased	3.5	4	0.5
46	5e+12	NDD unbiased	3.5	3.5	0
47	5e+12	NDD unbiased	3.5	4	0.5
50	1e+13	NDD unbiased	4	4	0
51	1e+13	NDD unbiased	3.5	3.5	0
52	1e+13	NDD unbiased	3.5	4	0.5
53	1e+13	NDD unbiased	3.5	3.5	0

Test Statistics (ns)

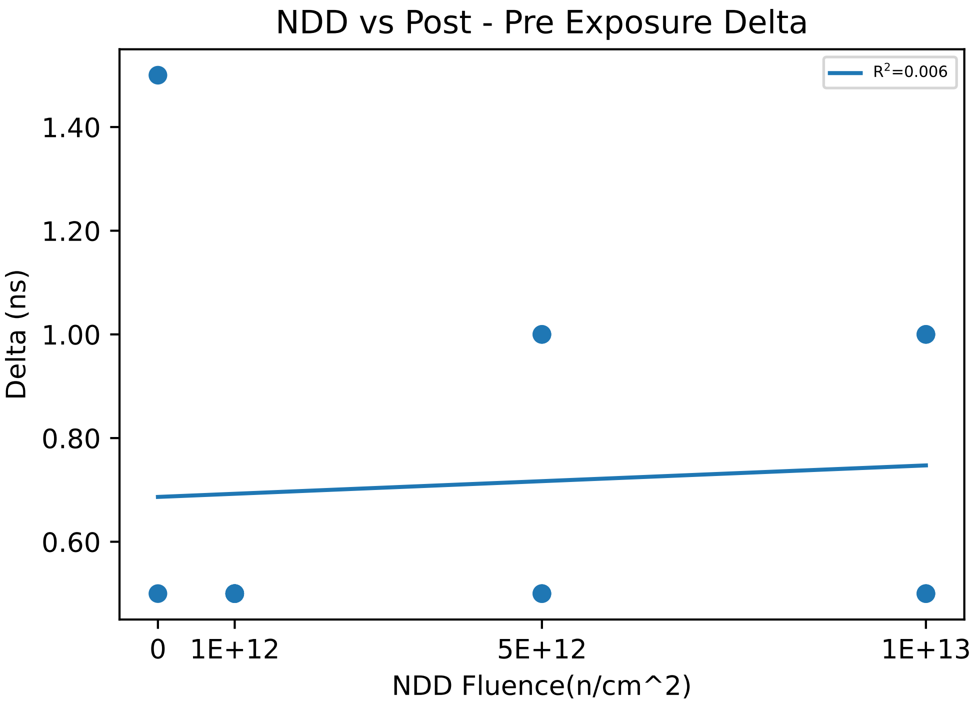
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.5	3.5	3.5	0	4	4	4	0	0.5	0.5	0.5	0
1e+12	3.5	3.5	3.5	0	3.5	3.75	4	0.28868	0	0.25	0.5	0.28868
5e+12	3.5	3.5	3.5	0	3.5	3.75	4	0.28868	0	0.25	0.5	0.28868
1e+13	3.5	3.625	4	0.25	3.5	3.75	4	0.28868	0	0.125	0.5	0.25

Device Test: 121.1 SW_T_PW_MIN_OFF(_Min Input PW Static HS Turn Off VIN_12V)



Test Results (Upper Limit = 12.0 (ns))

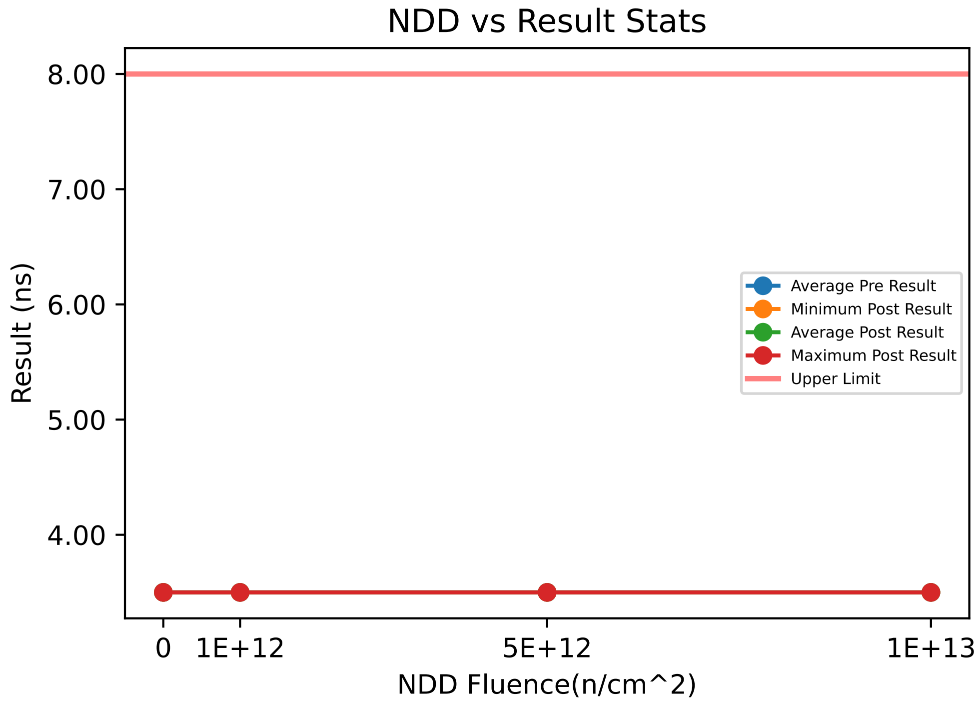
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	5.5	6	0.5
2	0	Correlation	5	6.5	1.5
30	1e+12	NDD unbiased	5.5	6	0.5
31	1e+12	NDD unbiased	5.5	6	0.5
32	1e+12	NDD unbiased	6	6.5	0.5
33	1e+12	NDD unbiased	5	5.5	0.5
44	5e+12	NDD unbiased	5	6	1
45	5e+12	NDD unbiased	6	6.5	0.5
46	5e+12	NDD unbiased	5.5	6.5	1
47	5e+12	NDD unbiased	6	6.5	0.5
50	1e+13	NDD unbiased	6	7	1
51	1e+13	NDD unbiased	5.5	6	0.5
52	1e+13	NDD unbiased	5.5	6.5	1
53	1e+13	NDD unbiased	5	5.5	0.5

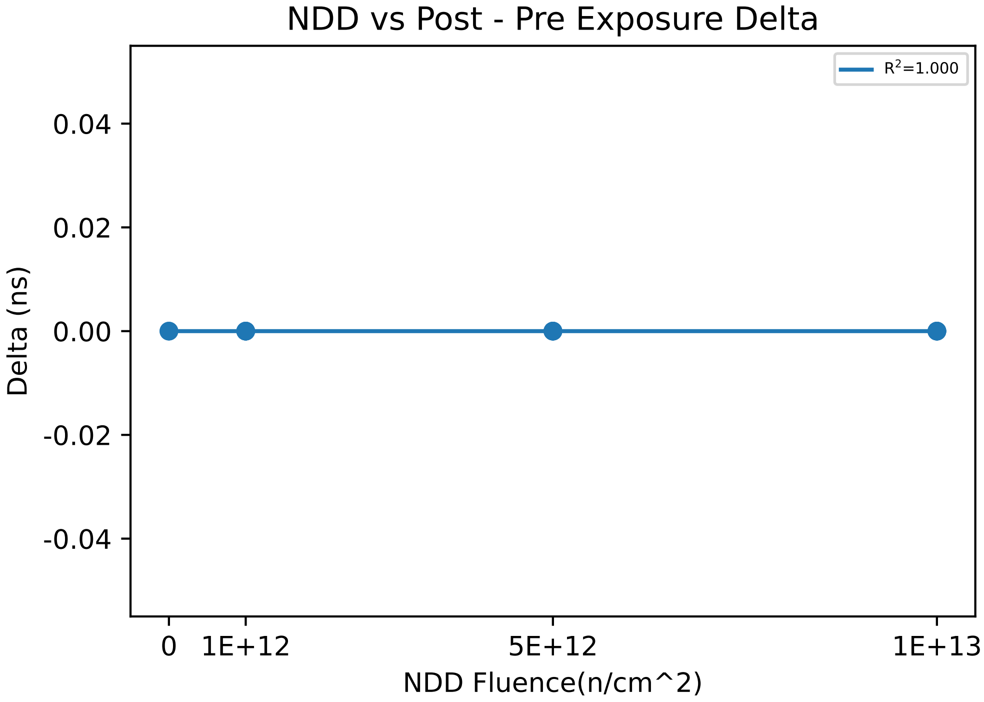


Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5	5.25	5.5	0.35355	6	6.25	6.5	0.35355	0.5	1	1.5	0.70711
1e+12	5	5.5	6	0.40825	5.5	6	6.5	0.40825	0.5	0.5	0.5	0
5e+12	5	5.625	6	0.47871	6	6.375	6.5	0.25	0.5	0.75	1	0.28868
1e+13	5	5.5	6	0.40825	5.5	6.25	7	0.6455	0.5	0.75	1	0.28868

Device Test: 121.2 SW_T_PW_MIN(_Min Input PW Static LS Turn On VIN_12V)





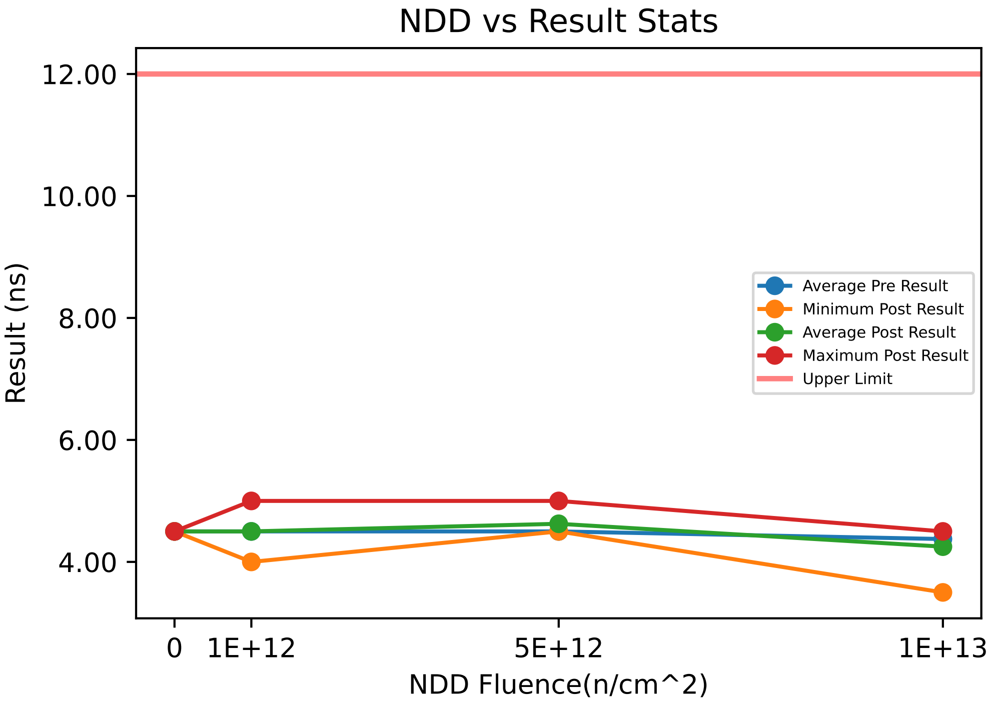
Test Results (Upper Limit = 8.0 (ns))

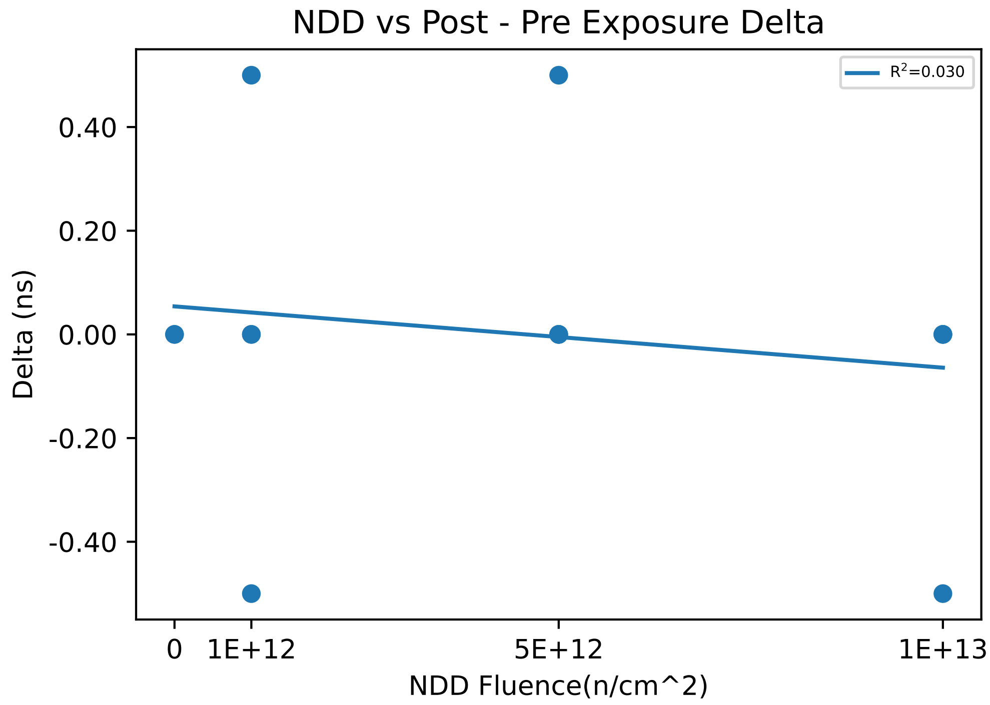
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	3.5	3.5	0
2	0	Correlation	3.5	3.5	0
30	1e+12	NDD unbiased	3.5	3.5	0
31	1e+12	NDD unbiased	3.5	3.5	0
32	1e+12	NDD unbiased	3.5	3.5	0
33	1e+12	NDD unbiased	3.5	3.5	0
44	5e+12	NDD unbiased	3.5	3.5	0
45	5e+12	NDD unbiased	3.5	3.5	0
46	5e+12	NDD unbiased	3.5	3.5	0
47	5e+12	NDD unbiased	3.5	3.5	0
50	1e+13	NDD unbiased	3.5	3.5	0
51	1e+13	NDD unbiased	3.5	3.5	0
52	1e+13	NDD unbiased	3.5	3.5	0
53	1e+13	NDD unbiased	3.5	3.5	0

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.5	3.5	3.5	0	3.5	3.5	3.5	0	0	0	0	0
1e+12	3.5	3.5	3.5	0	3.5	3.5	3.5	0	0	0	0	0
5e+12	3.5	3.5	3.5	0	3.5	3.5	3.5	0	0	0	0	0
1e+13	3.5	3.5	3.5	0	3.5	3.5	3.5	0	0	0	0	0

Device Test: 121.3 SW_T_PW_MIN_OFF(_Min Input PW Static LS Turn Off VIN_12V)





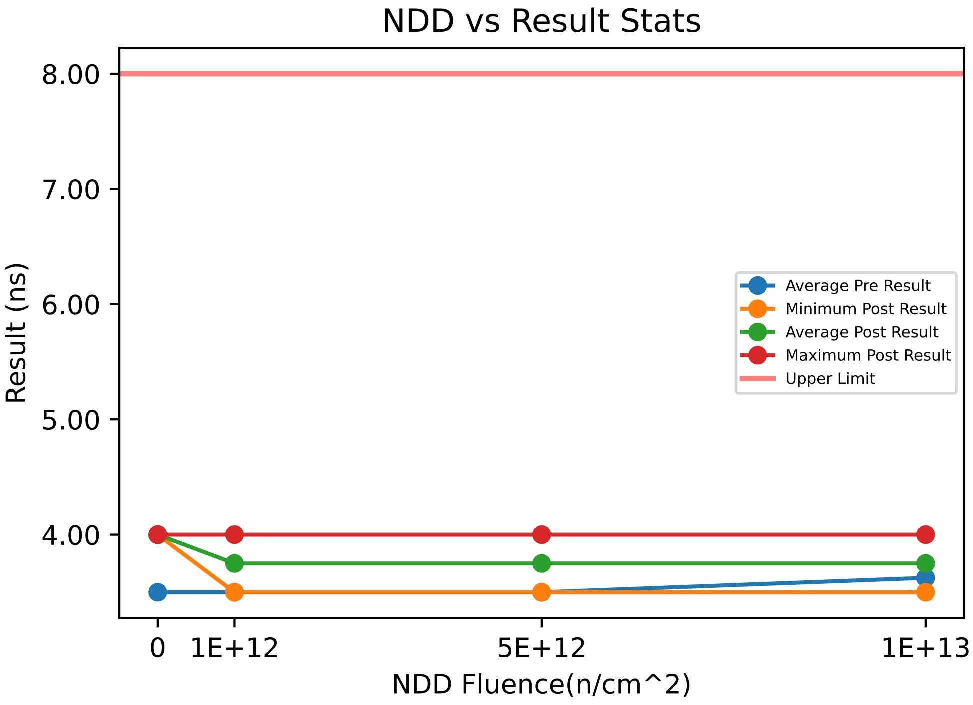
Test Results (Upper Limit = 12.0 (ns))

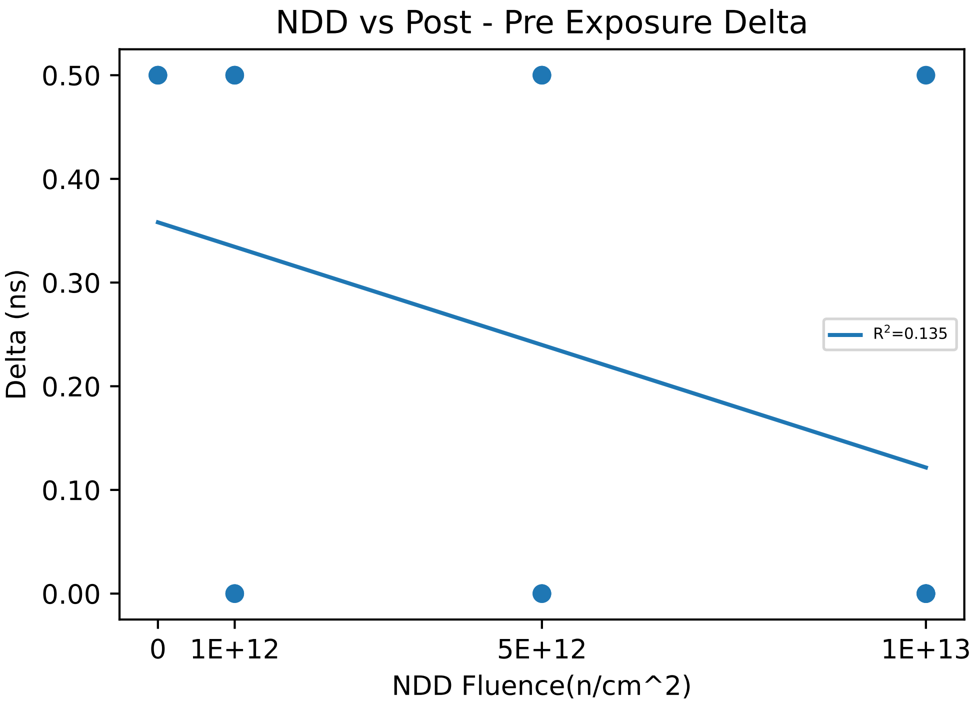
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	4.5	4.5	0
2	0	Correlation	4.5	4.5	0
30	1e+12	NDD unbiased	4	4.5	0.5
31	1e+12	NDD unbiased	4.5	4	-0.5
32	1e+12	NDD unbiased	4.5	4.5	0
33	1e+12	NDD unbiased	5	5	0
44	5e+12	NDD unbiased	5	5	0
45	5e+12	NDD unbiased	4	4.5	0.5
46	5e+12	NDD unbiased	4.5	4.5	0
47	5e+12	NDD unbiased	4.5	4.5	0
50	1e+13	NDD unbiased	5	4.5	-0.5
51	1e+13	NDD unbiased	3.5	3.5	0
52	1e+13	NDD unbiased	4.5	4.5	0
53	1e+13	NDD unbiased	4.5	4.5	0

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.5	4.5	4.5	0	4.5	4.5	4.5	0	0	0	0	0
1e+12	4	4.5	5	0.40825	4	4.5	5	0.40825	-0.5	0	0.5	0.40825
5e+12	4	4.5	5	0.40825	4.5	4.625	5	0.25	0	0.125	0.5	0.25
1e+13	3.5	4.375	5	0.62915	3.5	4.25	4.5	0.5	-0.5	-0.125	0	0.25

Device Test: 121.4 SW_T_PW_MIN(_Min Input PW Static HS Turn On SW=100V VIN_12V)


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

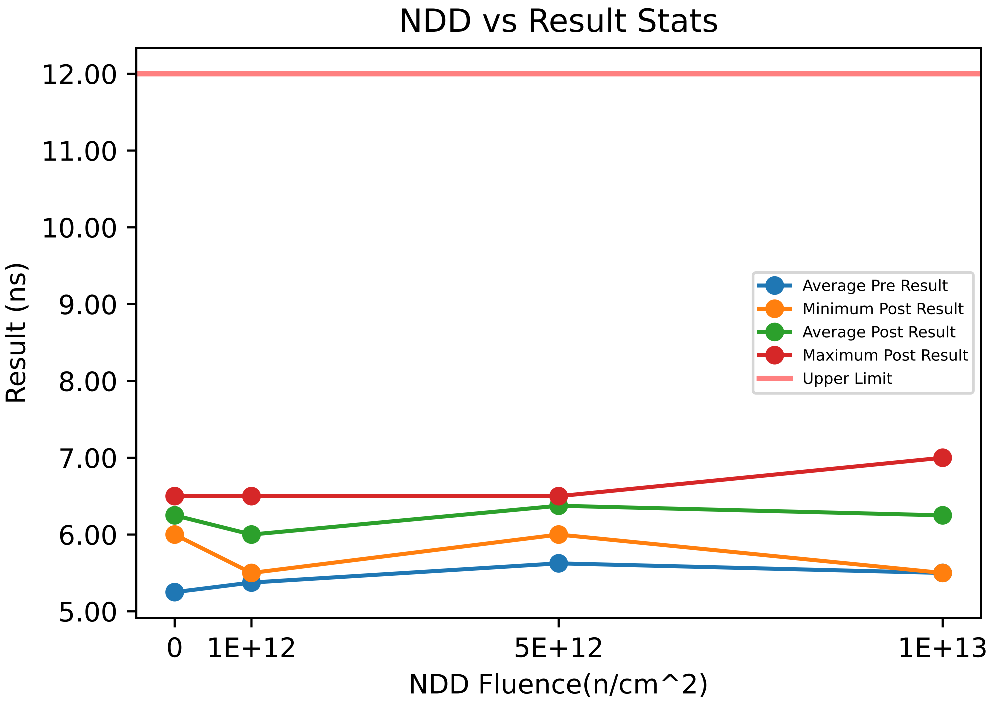
Test Results (Upper Limit = 8.0 (ns))

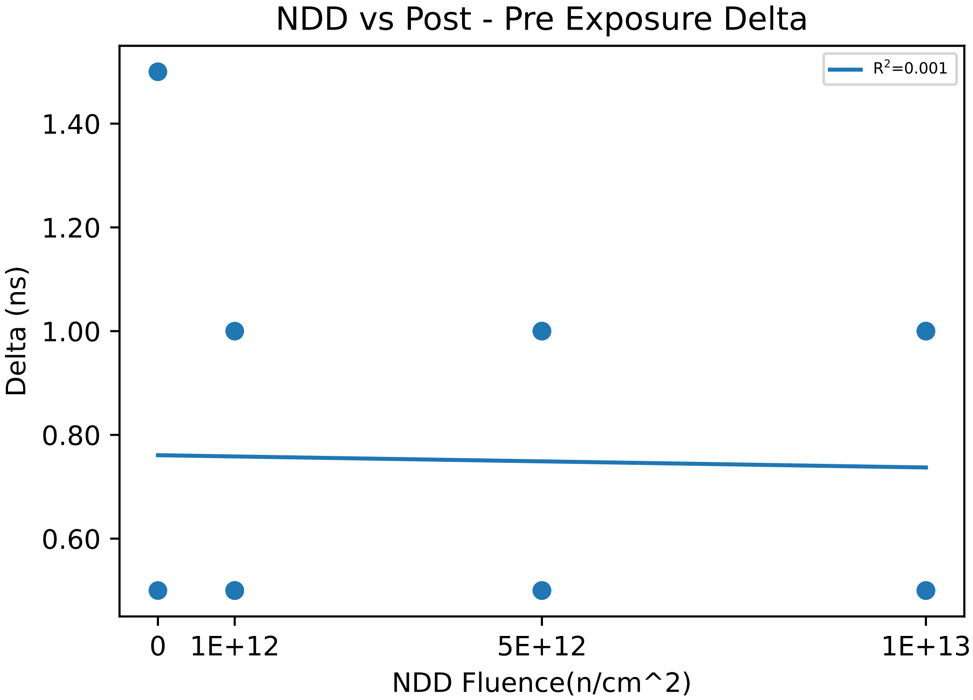
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	3.5	4	0.5
2	0	Correlation	3.5	4	0.5
30	1e+12	NDD unbiased	3.5	3.5	0
31	1e+12	NDD unbiased	3.5	4	0.5
32	1e+12	NDD unbiased	3.5	4	0.5
33	1e+12	NDD unbiased	3.5	3.5	0
44	5e+12	NDD unbiased	3.5	3.5	0
45	5e+12	NDD unbiased	3.5	4	0.5
46	5e+12	NDD unbiased	3.5	3.5	0
47	5e+12	NDD unbiased	3.5	4	0.5
50	1e+13	NDD unbiased	4	4	0
51	1e+13	NDD unbiased	3.5	3.5	0
52	1e+13	NDD unbiased	3.5	4	0.5
53	1e+13	NDD unbiased	3.5	3.5	0

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.5	3.5	3.5	0	4	4	4	0	0.5	0.5	0.5	0
1e+12	3.5	3.5	3.5	0	3.5	3.75	4	0.28868	0	0.25	0.5	0.28868
5e+12	3.5	3.5	3.5	0	3.5	3.75	4	0.28868	0	0.25	0.5	0.28868
1e+13	3.5	3.625	4	0.25	3.5	3.75	4	0.28868	0	0.125	0.5	0.25

Device Test: 121.5 SW_T_PW_MIN_OFF(_Min Input PW Static HS Turn Off SW=100V VIN_12V)





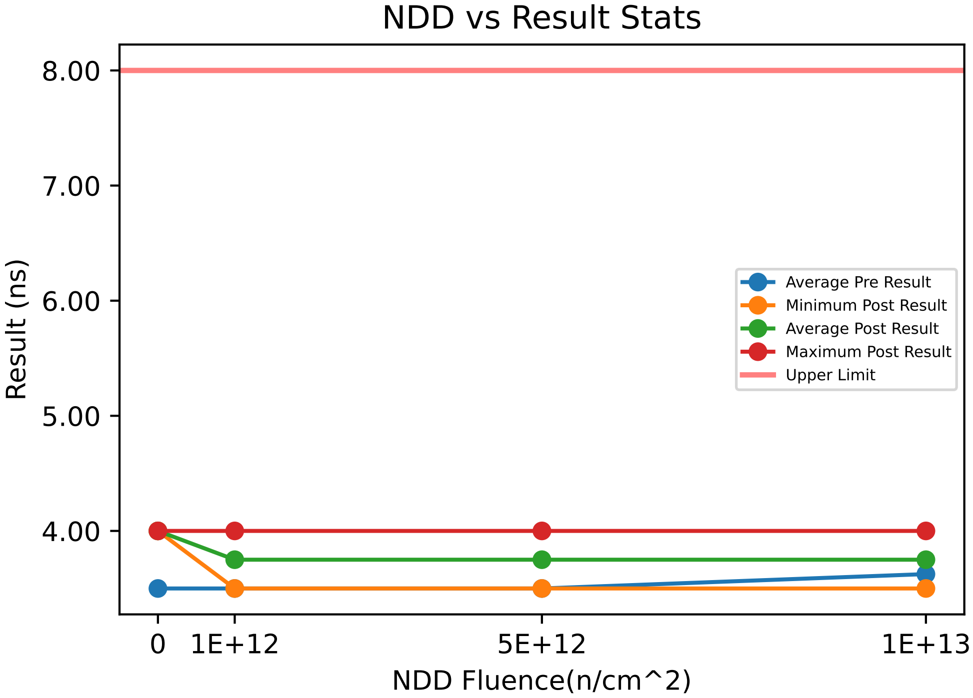
Test Results (Upper Limit = 12.0 (ns))

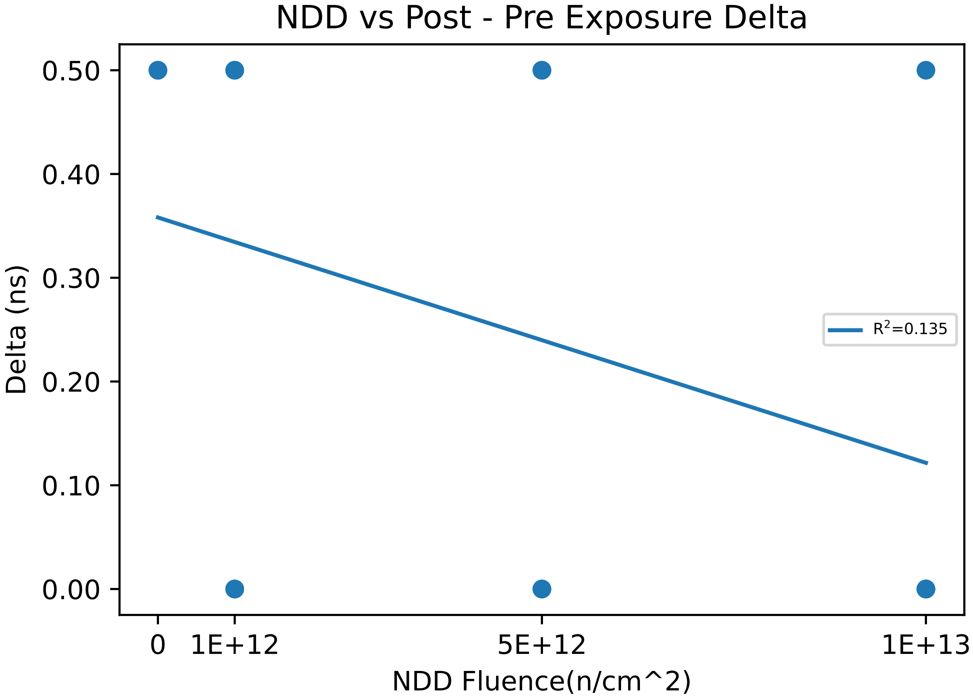
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	5.5	6	0.5
2	0	Correlation	5	6.5	1.5
30	1e+12	NDD unbiased	5.5	6	0.5
31	1e+12	NDD unbiased	5	6	1
32	1e+12	NDD unbiased	6	6.5	0.5
33	1e+12	NDD unbiased	5	5.5	0.5
44	5e+12	NDD unbiased	5	6	1
45	5e+12	NDD unbiased	6	6.5	0.5
46	5e+12	NDD unbiased	5.5	6.5	1
47	5e+12	NDD unbiased	6	6.5	0.5
50	1e+13	NDD unbiased	6	7	1
51	1e+13	NDD unbiased	5.5	6	0.5
52	1e+13	NDD unbiased	5.5	6.5	1
53	1e+13	NDD unbiased	5	5.5	0.5

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5	5.25	5.5	0.35355	6	6.25	6.5	0.35355	0.5	1	1.5	0.70711
1e+12	5	5.375	6	0.47871	5.5	6	6.5	0.40825	0.5	0.625	1	0.25
5e+12	5	5.625	6	0.47871	6	6.375	6.5	0.25	0.5	0.75	1	0.28868
1e+13	5	5.5	6	0.40825	5.5	6.25	7	0.6455	0.5	0.75	1	0.28868

Device Test: 122.0 SW_T_PW_MIN(_Min Input PW Static HS Turn On VIN_14V)





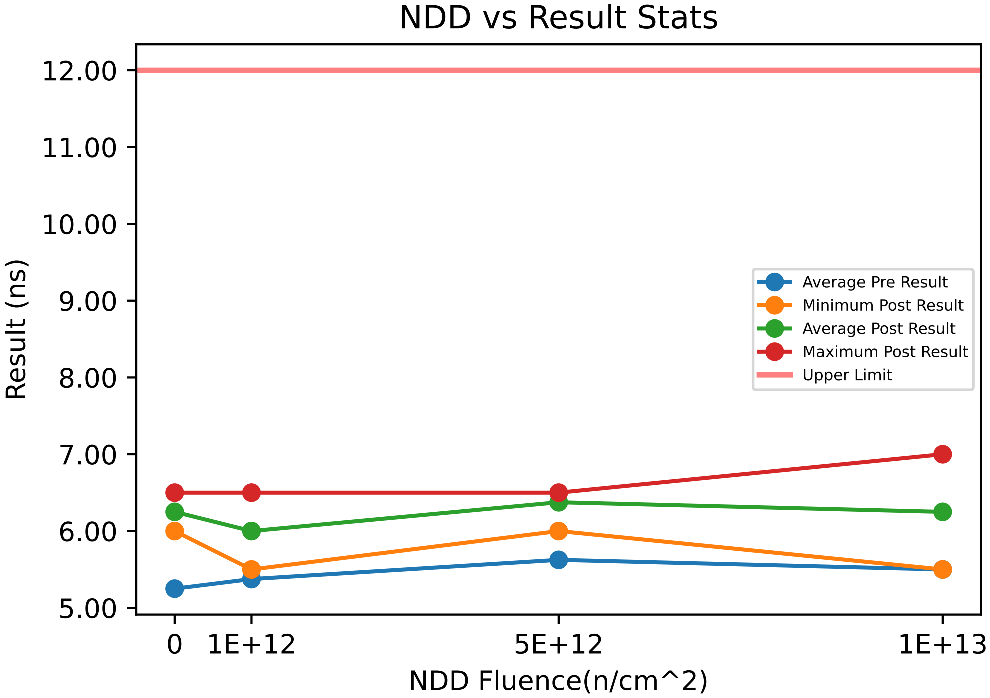
Test Results (Upper Limit = 8.0 (ns))

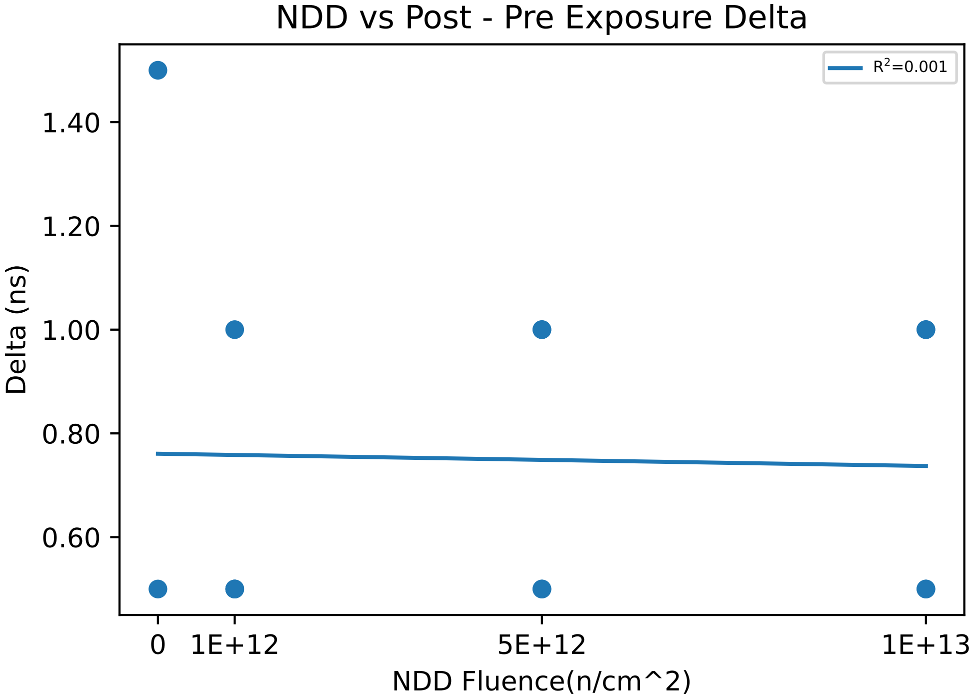
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	3.5	4	0.5
2	0	Correlation	3.5	4	0.5
30	1e+12	NDD unbiased	3.5	3.5	0
31	1e+12	NDD unbiased	3.5	4	0.5
32	1e+12	NDD unbiased	3.5	4	0.5
33	1e+12	NDD unbiased	3.5	3.5	0
44	5e+12	NDD unbiased	3.5	3.5	0
45	5e+12	NDD unbiased	3.5	4	0.5
46	5e+12	NDD unbiased	3.5	3.5	0
47	5e+12	NDD unbiased	3.5	4	0.5
50	1e+13	NDD unbiased	4	4	0
51	1e+13	NDD unbiased	3.5	3.5	0
52	1e+13	NDD unbiased	3.5	4	0.5
53	1e+13	NDD unbiased	3.5	3.5	0

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.5	3.5	3.5	0	4	4	4	0	0.5	0.5	0.5	0
1e+12	3.5	3.5	3.5	0	3.5	3.75	4	0.28868	0	0.25	0.5	0.28868
5e+12	3.5	3.5	3.5	0	3.5	3.75	4	0.28868	0	0.25	0.5	0.28868
1e+13	3.5	3.625	4	0.25	3.5	3.75	4	0.28868	0	0.125	0.5	0.25

Device Test: 122.1 SW_T_PW_MIN_OFF(_Min Input PW Static HS Turn Off VIN_14V)





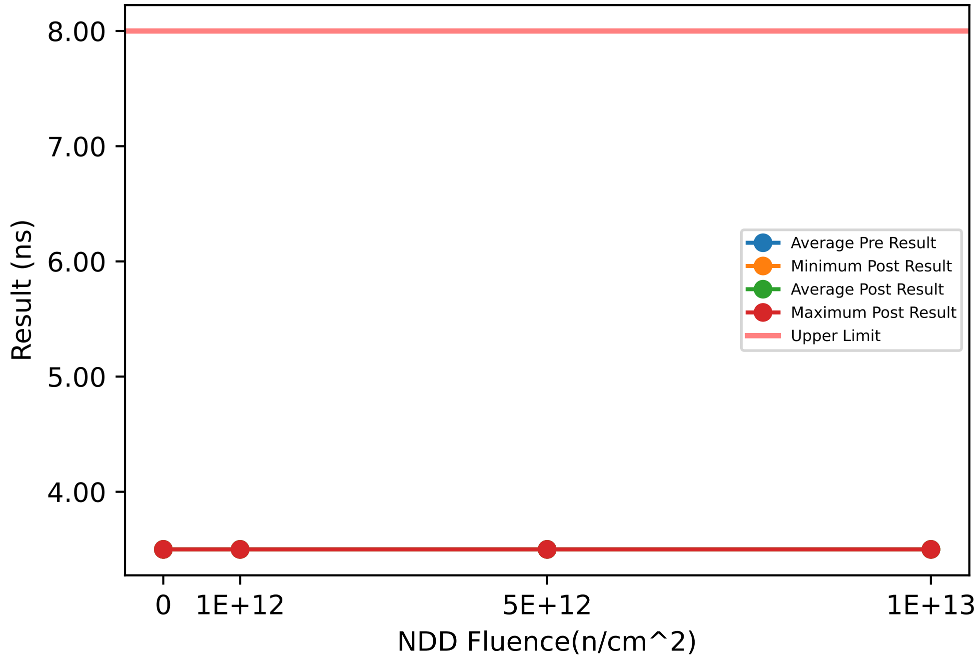
Test Results (Upper Limit = 12.0 (ns))

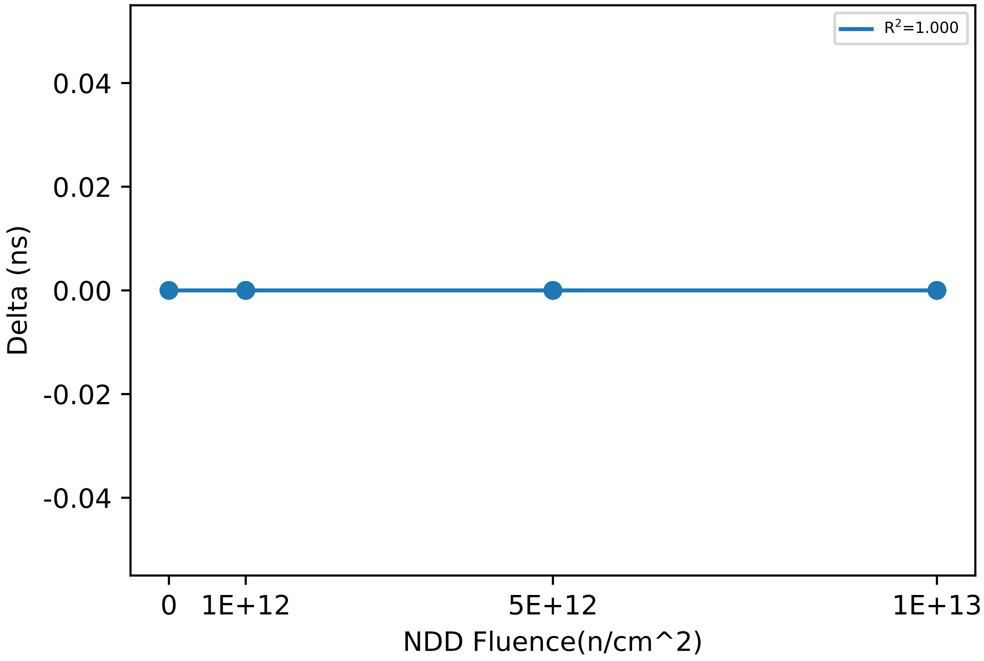
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	5.5	6	0.5
2	0	Correlation	5	6.5	1.5
30	1e+12	NDD unbiased	5.5	6	0.5
31	1e+12	NDD unbiased	5	6	1
32	1e+12	NDD unbiased	6	6.5	0.5
33	1e+12	NDD unbiased	5	5.5	0.5
44	5e+12	NDD unbiased	5	6	1
45	5e+12	NDD unbiased	6	6.5	0.5
46	5e+12	NDD unbiased	5.5	6.5	1
47	5e+12	NDD unbiased	6	6.5	0.5
50	1e+13	NDD unbiased	6	7	1
51	1e+13	NDD unbiased	5.5	6	0.5
52	1e+13	NDD unbiased	5.5	6.5	1
53	1e+13	NDD unbiased	5	5.5	0.5

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5	5.25	5.5	0.35355	6	6.25	6.5	0.35355	0.5	1	1.5	0.70711
1e+12	5	5.375	6	0.47871	5.5	6	6.5	0.40825	0.5	0.625	1	0.25
5e+12	5	5.625	6	0.47871	6	6.375	6.5	0.25	0.5	0.75	1	0.28868
1e+13	5	5.5	6	0.40825	5.5	6.25	7	0.6455	0.5	0.75	1	0.28868

Device Test: 122.2 SW_T_PW_MIN(_Min Input PW Static LS Turn On VIN_14V)


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

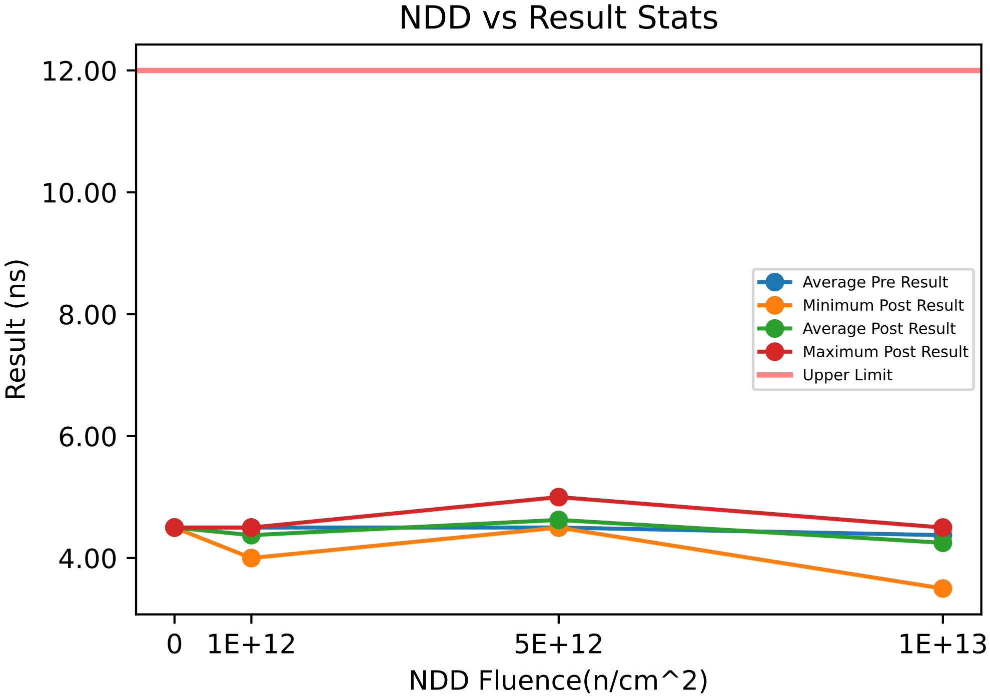
Test Results (Upper Limit = 8.0 (ns))

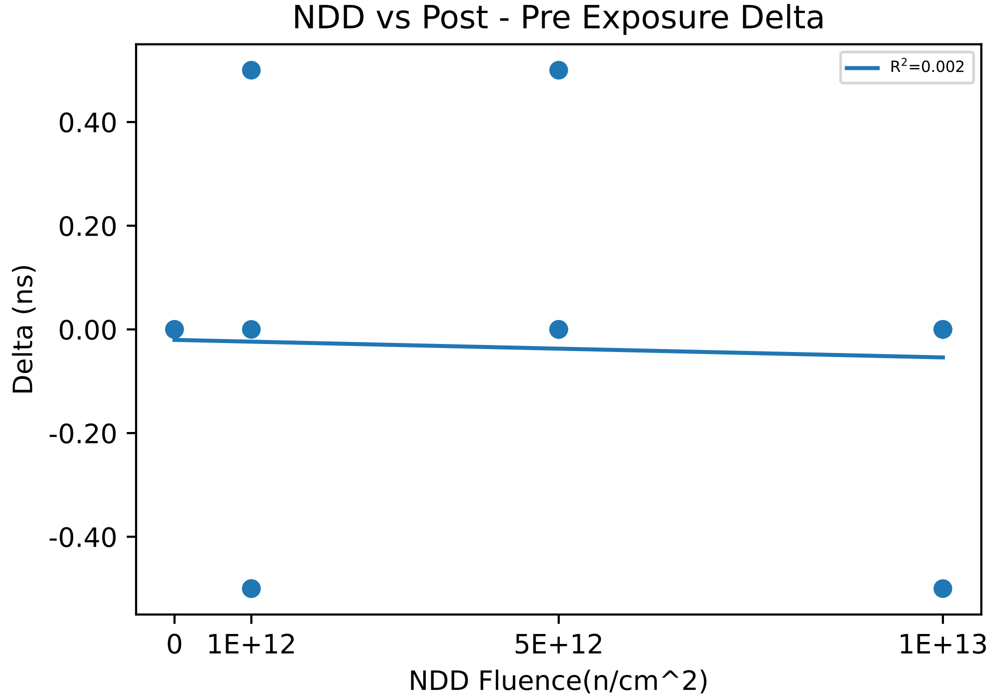
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	3.5	3.5	0
2	0	Correlation	3.5	3.5	0
30	1e+12	NDD unbiased	3.5	3.5	0
31	1e+12	NDD unbiased	3.5	3.5	0
32	1e+12	NDD unbiased	3.5	3.5	0
33	1e+12	NDD unbiased	3.5	3.5	0
44	5e+12	NDD unbiased	3.5	3.5	0
45	5e+12	NDD unbiased	3.5	3.5	0
46	5e+12	NDD unbiased	3.5	3.5	0
47	5e+12	NDD unbiased	3.5	3.5	0
50	1e+13	NDD unbiased	3.5	3.5	0
51	1e+13	NDD unbiased	3.5	3.5	0
52	1e+13	NDD unbiased	3.5	3.5	0
53	1e+13	NDD unbiased	3.5	3.5	0

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.5	3.5	3.5	0	3.5	3.5	3.5	0	0	0	0	0
1e+12	3.5	3.5	3.5	0	3.5	3.5	3.5	0	0	0	0	0
5e+12	3.5	3.5	3.5	0	3.5	3.5	3.5	0	0	0	0	0
1e+13	3.5	3.5	3.5	0	3.5	3.5	3.5	0	0	0	0	0

Device Test: 122.3 SW_T_PW_MIN_OFF(_Min Input PW Static LS Turn Off VIN_14V)





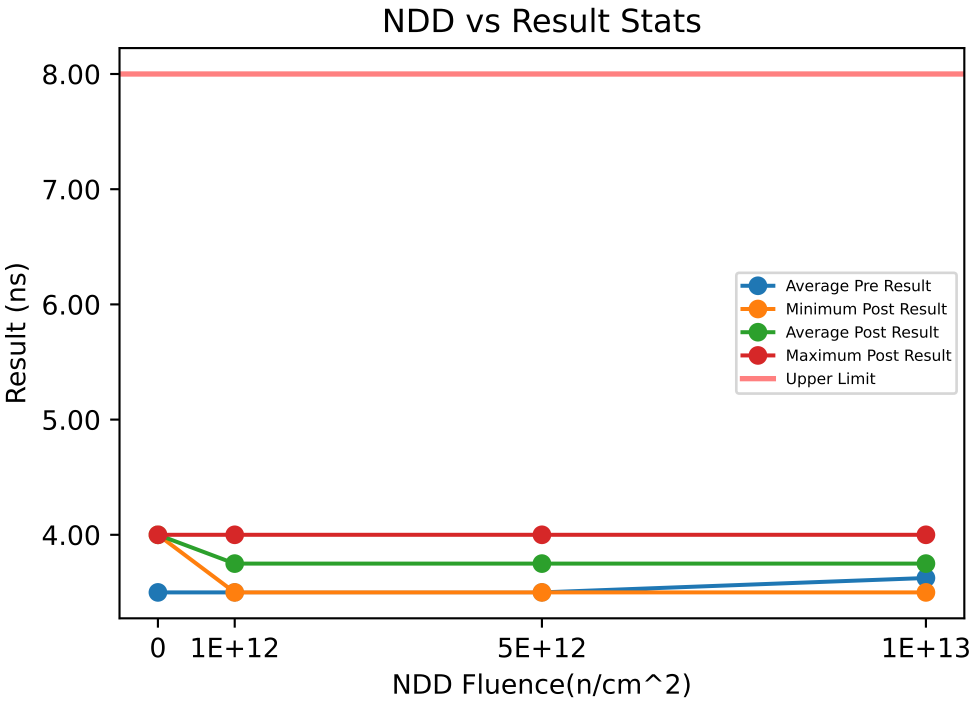
Test Results (Upper Limit = 12.0 (ns))

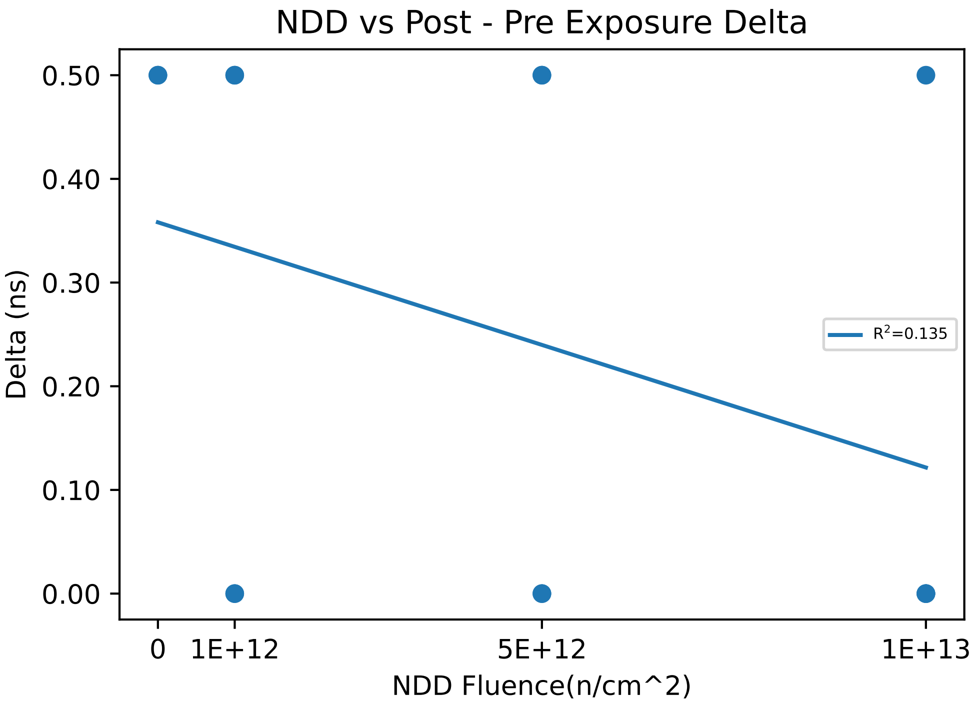
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	4.5	4.5	0
2	0	Correlation	4.5	4.5	0
30	1e+12	NDD unbiased	4	4.5	0.5
31	1e+12	NDD unbiased	4.5	4	-0.5
32	1e+12	NDD unbiased	4.5	4.5	0
33	1e+12	NDD unbiased	5	4.5	-0.5
44	5e+12	NDD unbiased	5	5	0
45	5e+12	NDD unbiased	4	4.5	0.5
46	5e+12	NDD unbiased	4.5	4.5	0
47	5e+12	NDD unbiased	4.5	4.5	0
50	1e+13	NDD unbiased	5	4.5	-0.5
51	1e+13	NDD unbiased	3.5	3.5	0
52	1e+13	NDD unbiased	4.5	4.5	0
53	1e+13	NDD unbiased	4.5	4.5	0

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.5	4.5	4.5	0	4.5	4.5	4.5	0	0	0	0	0
1e+12	4	4.5	5	0.40825	4	4.375	4.5	0.25	-0.5	-0.125	0.5	0.47871
5e+12	4	4.5	5	0.40825	4.5	4.625	5	0.25	0	0.125	0.5	0.25
1e+13	3.5	4.375	5	0.62915	3.5	4.25	4.5	0.5	-0.5	-0.125	0	0.25

Device Test: 122.4 SW_T_PW_MIN(_Min Input PW Static HS Turn On SW=100V VIN_14V)


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

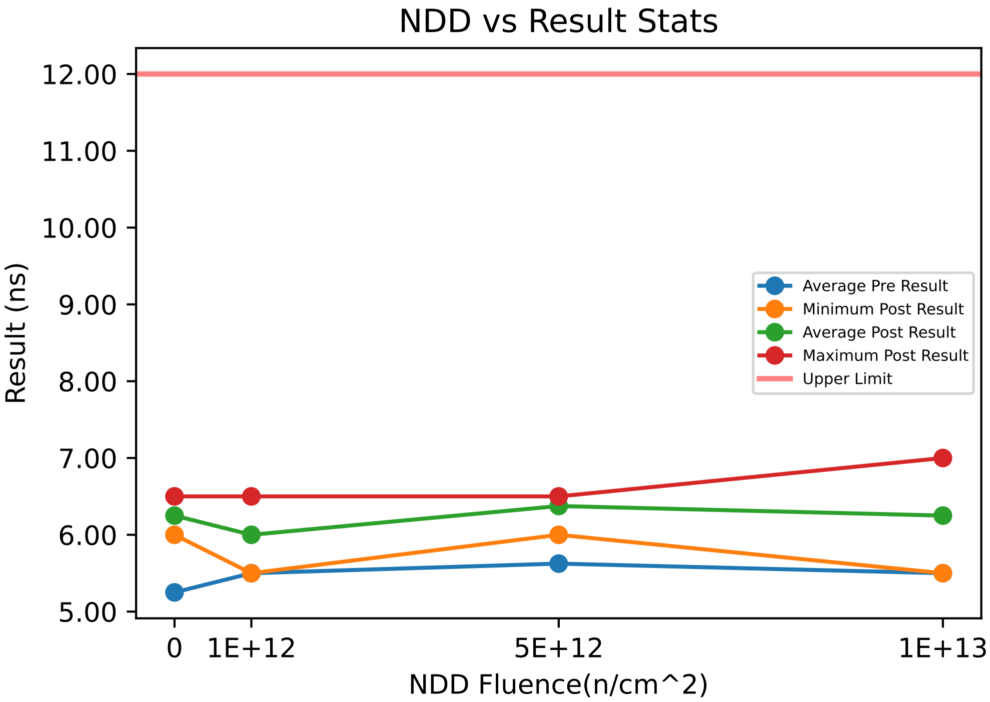
Test Results (Upper Limit = 8.0 (ns))

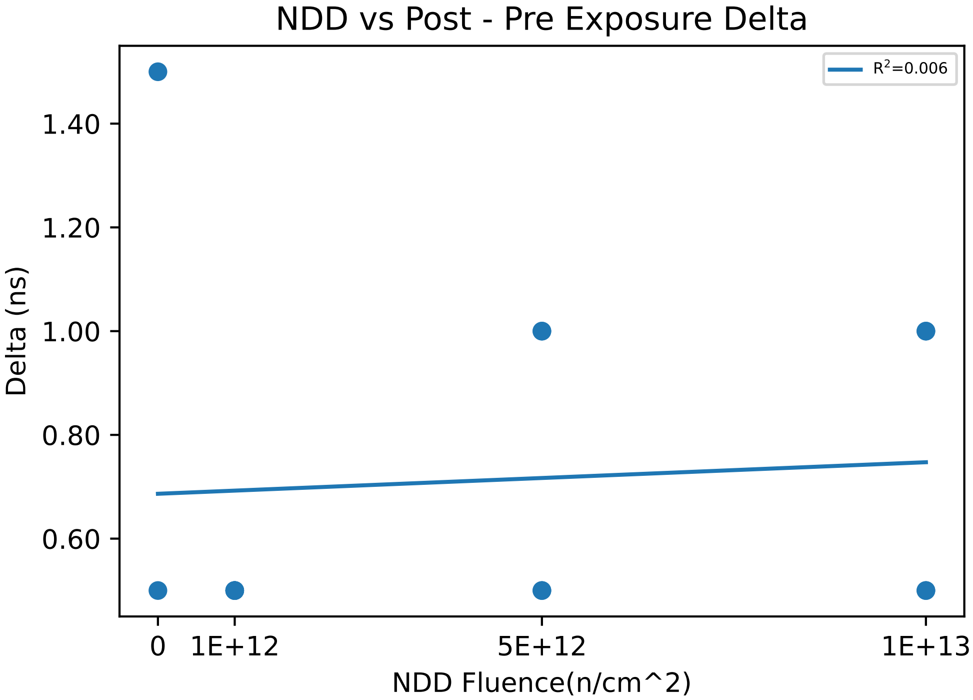
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	3.5	4	0.5
2	0	Correlation	3.5	4	0.5
30	1e+12	NDD unbiased	3.5	3.5	0
31	1e+12	NDD unbiased	3.5	4	0.5
32	1e+12	NDD unbiased	3.5	4	0.5
33	1e+12	NDD unbiased	3.5	3.5	0
44	5e+12	NDD unbiased	3.5	3.5	0
45	5e+12	NDD unbiased	3.5	4	0.5
46	5e+12	NDD unbiased	3.5	3.5	0
47	5e+12	NDD unbiased	3.5	4	0.5
50	1e+13	NDD unbiased	4	4	0
51	1e+13	NDD unbiased	3.5	3.5	0
52	1e+13	NDD unbiased	3.5	4	0.5
53	1e+13	NDD unbiased	3.5	3.5	0

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.5	3.5	3.5	0	4	4	4	0	0.5	0.5	0.5	0
1e+12	3.5	3.5	3.5	0	3.5	3.75	4	0.28868	0	0.25	0.5	0.28868
5e+12	3.5	3.5	3.5	0	3.5	3.75	4	0.28868	0	0.25	0.5	0.28868
1e+13	3.5	3.625	4	0.25	3.5	3.75	4	0.28868	0	0.125	0.5	0.25

Device Test: 122.5 SW_T_PW_MIN_OFF(_Min Input PW Static HS Turn Off SW=100V VIN_14V)





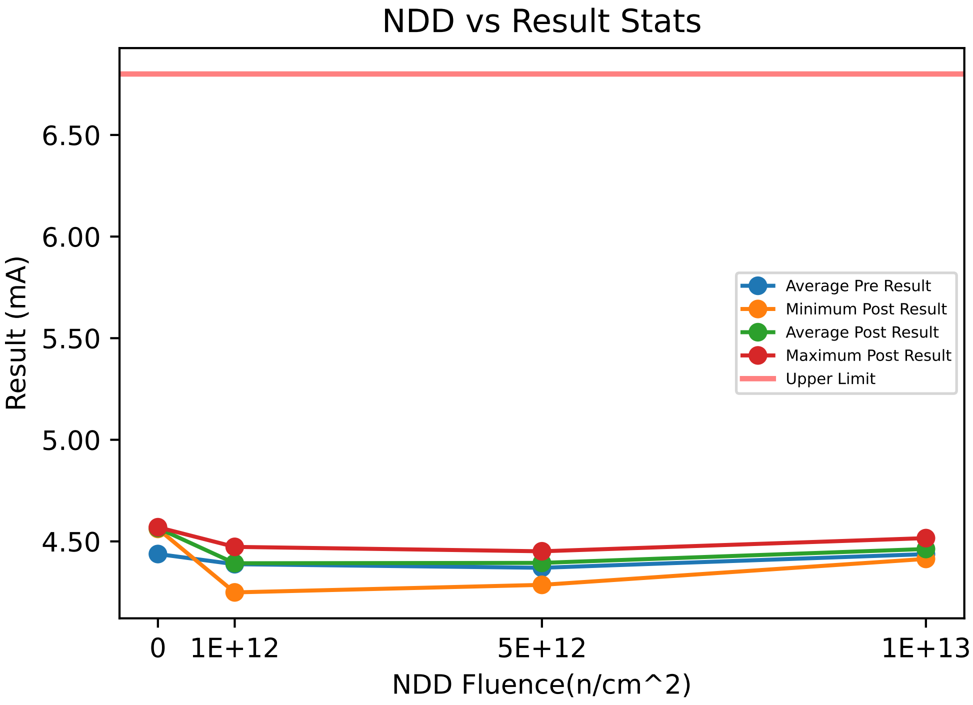
Test Results (Upper Limit = 12.0 (ns))

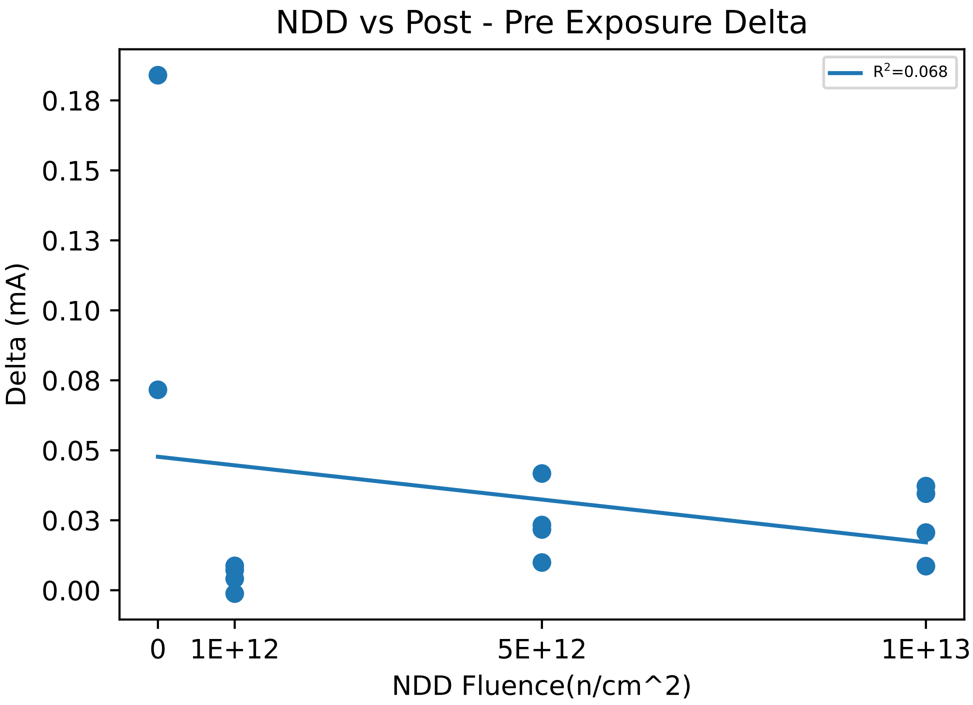
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	5.5	6	0.5
2	0	Correlation	5	6.5	1.5
30	1e+12	NDD unbiased	5.5	6	0.5
31	1e+12	NDD unbiased	5.5	6	0.5
32	1e+12	NDD unbiased	6	6.5	0.5
33	1e+12	NDD unbiased	5	5.5	0.5
44	5e+12	NDD unbiased	5	6	1
45	5e+12	NDD unbiased	6	6.5	0.5
46	5e+12	NDD unbiased	5.5	6.5	1
47	5e+12	NDD unbiased	6	6.5	0.5
50	1e+13	NDD unbiased	6	7	1
51	1e+13	NDD unbiased	5.5	6	0.5
52	1e+13	NDD unbiased	5.5	6.5	1
53	1e+13	NDD unbiased	5	5.5	0.5

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5	5.25	5.5	0.35355	6	6.25	6.5	0.35355	0.5	1	1.5	0.70711
1e+12	5	5.5	6	0.40825	5.5	6	6.5	0.40825	0.5	0.5	0.5	0
5e+12	5	5.625	6	0.47871	6	6.375	6.5	0.25	0.5	0.75	1	0.28868
1e+13	5	5.5	6	0.40825	5.5	6.25	7	0.6455	0.5	0.75	1	0.28868

Device Test: 35.0 IQ_LS_PWM(_Iq LS VIN PWM VIN_10V)





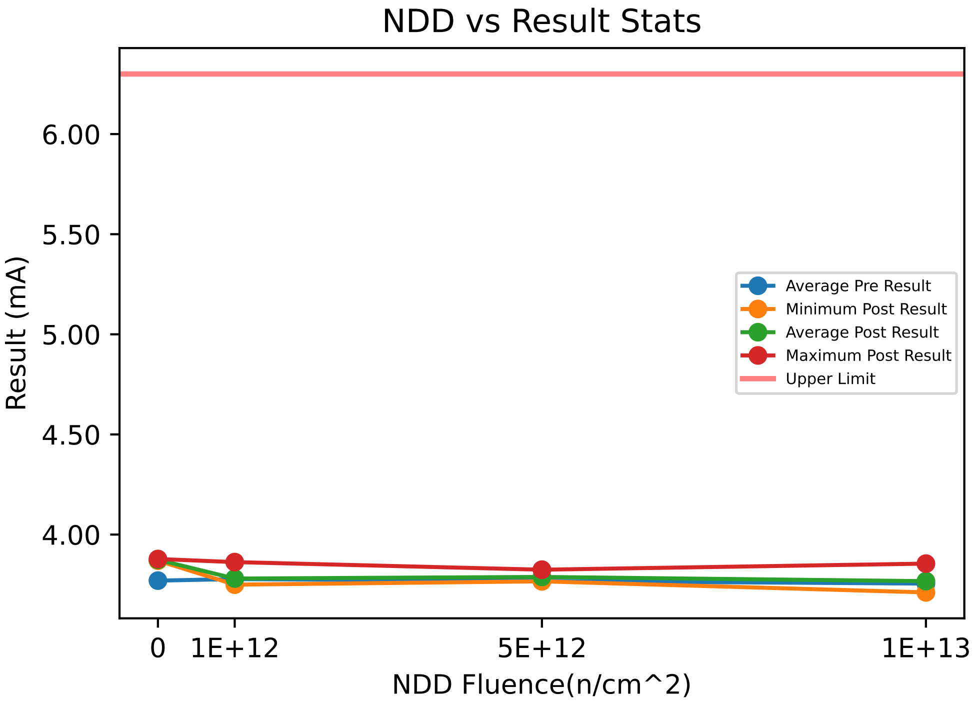
Test Results (Upper Limit = 6.8 (mA))

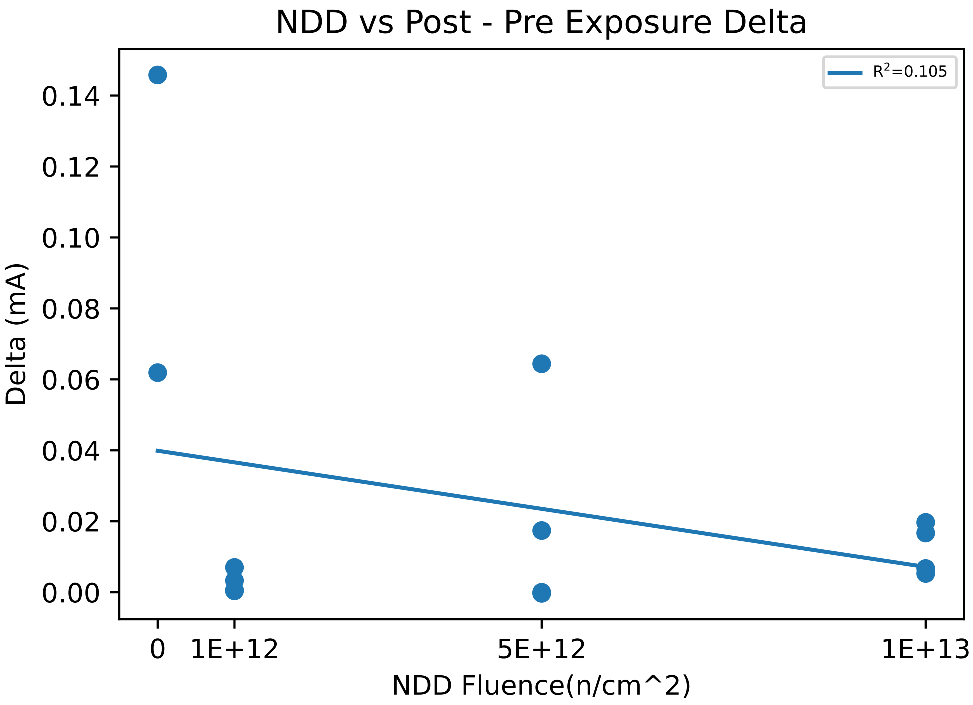
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	4.3857	4.5697	0.184
2	0	Correlation	4.49	4.5616	0.0716
30	1e+12	NDD unbiased	4.4658	4.473	0.0072
31	1e+12	NDD unbiased	4.4693	4.4681	-0.0012
32	1e+12	NDD unbiased	4.3756	4.3797	0.0041
33	1e+12	NDD unbiased	4.2403	4.249	0.0087
44	5e+12	NDD unbiased	4.2628	4.2861	0.0233
45	5e+12	NDD unbiased	4.4077	4.4494	0.0417
46	5e+12	NDD unbiased	4.3685	4.3902	0.0217
47	5e+12	NDD unbiased	4.4414	4.4513	0.0099
50	1e+13	NDD unbiased	4.4436	4.4522	0.0086
51	1e+13	NDD unbiased	4.4816	4.5161	0.0345
52	1e+13	NDD unbiased	4.3766	4.4138	0.0372
53	1e+13	NDD unbiased	4.4475	4.4681	0.0206

Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.3857	4.4379	4.49	0.073751	4.5616	4.5656	4.5697	0.0057276	0.0716	0.1278	0.184	0.079479
1e+12	4.2403	4.3878	4.4693	0.10744	4.249	4.3925	4.473	0.1048	-0.0012	0.0047	0.0087	0.0043749
5e+12	4.2628	4.3701	4.4414	0.077488	4.2861	4.3942	4.4513	0.077479	0.0099	0.02415	0.0417	0.013138
1e+13	4.3766	4.4373	4.4816	0.043934	4.4138	4.4626	4.5161	0.042356	0.0086	0.025225	0.0372	0.013257

Device Test: 35.1 IQ_HS_PWM(_Iq HS BOOT PWM VIN_10V)





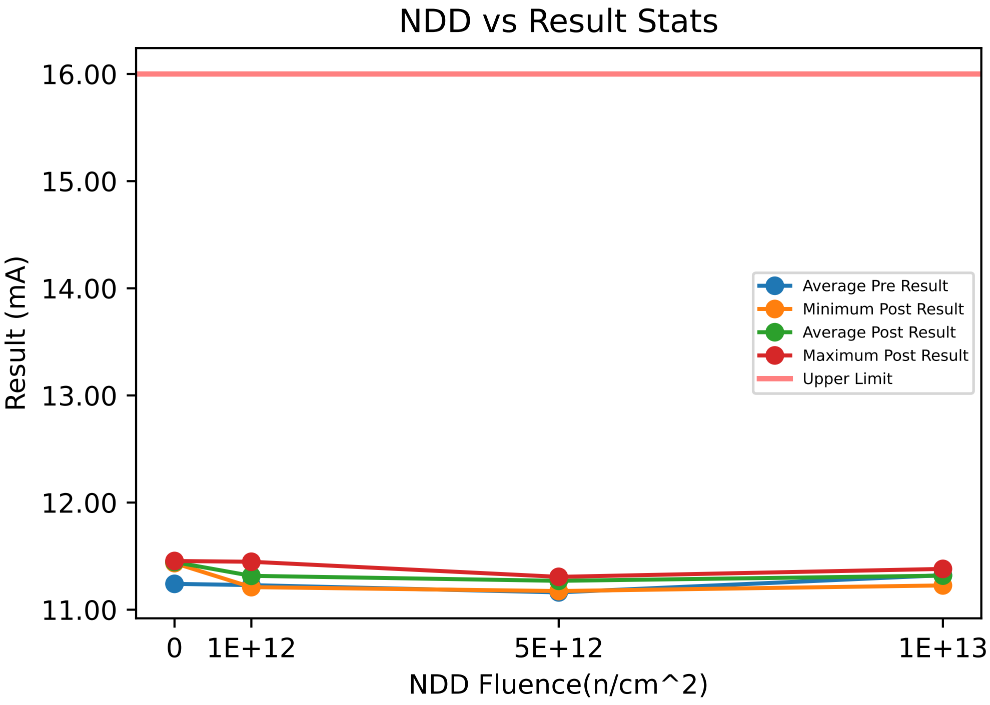
Test Results (Upper Limit = 6.3 (mA))

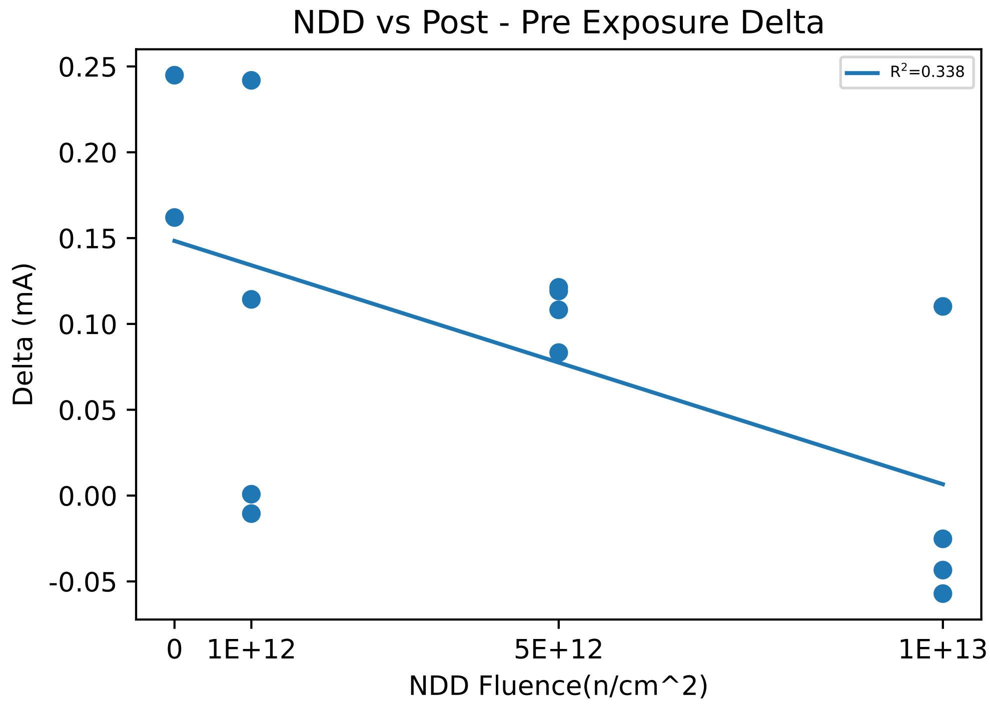
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	3.7323	3.8781	0.1458
2	0	Correlation	3.8078	3.8697	0.0619
30	1e+12	NDD unbiased	3.7514	3.7518	0.0004
31	1e+12	NDD unbiased	3.7466	3.7499	0.0033
32	1e+12	NDD unbiased	3.7506	3.7576	0.007
33	1e+12	NDD unbiased	3.8619	3.8625	0.0006
44	5e+12	NDD unbiased	3.8246	3.8246	0
45	5e+12	NDD unbiased	3.7154	3.7798	0.0644
46	5e+12	NDD unbiased	3.7667	3.7664	-0.0003
47	5e+12	NDD unbiased	3.7652	3.7826	0.0174
50	1e+13	NDD unbiased	3.7059	3.7112	0.0053
51	1e+13	NDD unbiased	3.7529	3.7726	0.0197
52	1e+13	NDD unbiased	3.7137	3.7304	0.0167
53	1e+13	NDD unbiased	3.8482	3.8549	0.0067

Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.7323	3.77	3.8078	0.053387	3.8697	3.8739	3.8781	0.0059397	0.0619	0.10385	0.1458	0.059326
1e+12	3.7466	3.7776	3.8619	0.056223	3.7499	3.7805	3.8625	0.054798	0.0004	0.002825	0.007	0.0030815
5e+12	3.7154	3.768	3.8246	0.044646	3.7664	3.7883	3.8246	0.02518	-0.0003	0.020375	0.0644	0.030494
1e+13	3.7059	3.7552	3.8482	0.065338	3.7112	3.7673	3.8549	0.063798	0.0053	0.0121	0.0197	0.0071722

Device Test: 35.10 I_OP_LS_PWM_2MHZ(_Iop LS VIN PWM 2MHz VIN_10V)





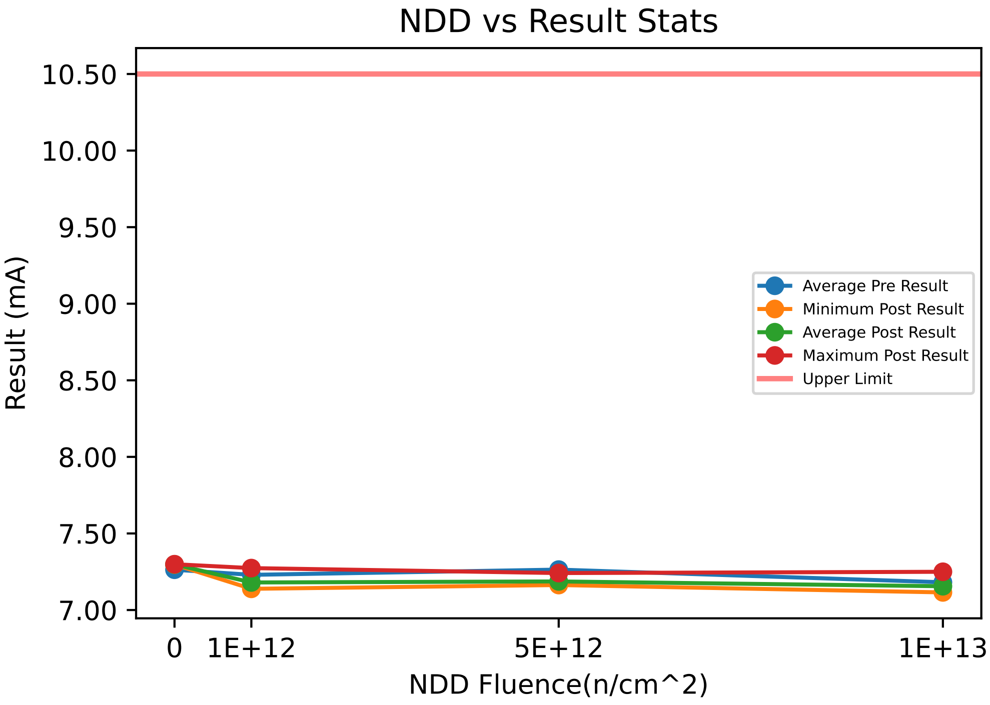
Test Results (Upper Limit = 16.0 (mA))

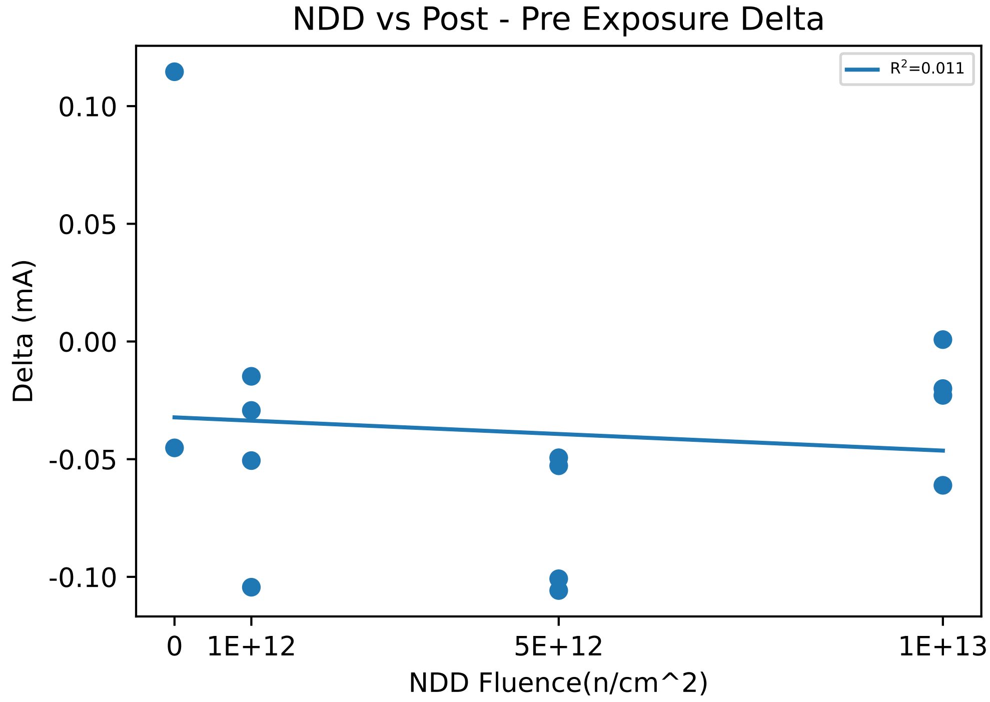
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	11.19	11.435	0.2449
2	0	Correlation	11.293	11.455	0.162
30	1e+12	NDD unbiased	11.322	11.322	0.0008
31	1e+12	NDD unbiased	11.206	11.447	0.2419
32	1e+12	NDD unbiased	11.17	11.284	0.1143
33	1e+12	NDD unbiased	11.221	11.211	-0.0105
44	5e+12	NDD unbiased	11.055	11.174	0.1192
45	5e+12	NDD unbiased	11.222	11.305	0.0833
46	5e+12	NDD unbiased	11.171	11.293	0.1213
47	5e+12	NDD unbiased	11.198	11.307	0.1082
50	1e+13	NDD unbiased	11.418	11.361	-0.0571
51	1e+13	NDD unbiased	11.116	11.227	0.1102
52	1e+13	NDD unbiased	11.329	11.304	-0.0252
53	1e+13	NDD unbiased	11.424	11.381	-0.0434

Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	11.19	11.241	11.293	0.072761	11.435	11.445	11.455	0.014142	0.162	0.20345	0.2449	0.058619
1e+12	11.17	11.23	11.322	0.064952	11.211	11.316	11.447	0.099047	-0.0105	0.086625	0.2419	0.11786
5e+12	11.055	11.162	11.222	0.073949	11.174	11.27	11.307	0.063878	0.0833	0.108	0.1213	0.01744
1e+13	11.116	11.322	11.424	0.14378	11.227	11.318	11.381	0.069195	-0.0571	-0.003875	0.1102	0.077164

Device Test: 35.11 I_OP_HS_PWM_2MHZ(_Iop HS BOOT PWM 2MHz VIN_10V)





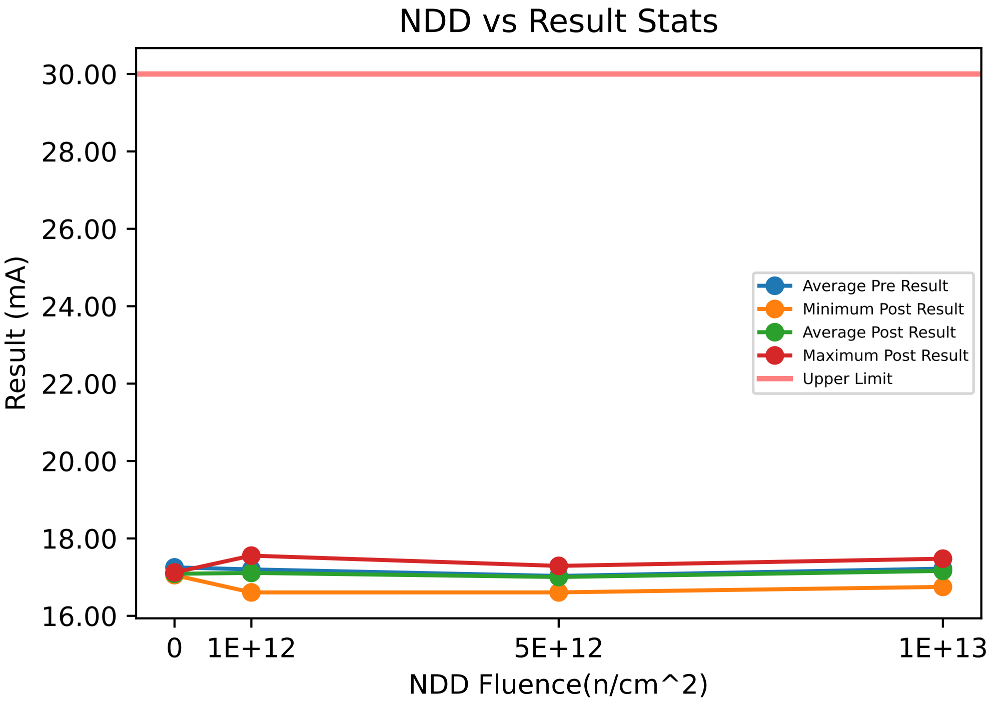
Test Results (Upper Limit = 10.5 (mA))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	7.182	7.2966	0.1146
2	0	Correlation	7.3443	7.2991	-0.0452
30	1e+12	NDD unbiased	7.1929	7.1636	-0.0293
31	1e+12	NDD unbiased	7.2429	7.1385	-0.1044
32	1e+12	NDD unbiased	7.1946	7.144	-0.0506
33	1e+12	NDD unbiased	7.2886	7.2738	-0.0148
44	5e+12	NDD unbiased	7.3472	7.2414	-0.1058
45	5e+12	NDD unbiased	7.2126	7.1632	-0.0494
46	5e+12	NDD unbiased	7.2748	7.174	-0.1008
47	5e+12	NDD unbiased	7.221	7.1682	-0.0528
50	1e+13	NDD unbiased	7.138	7.1151	-0.0229
51	1e+13	NDD unbiased	7.1958	7.1347	-0.0611
52	1e+13	NDD unbiased	7.1211	7.1219	0.0008
53	1e+13	NDD unbiased	7.2697	7.2497	-0.02

Test Statistics (mA)

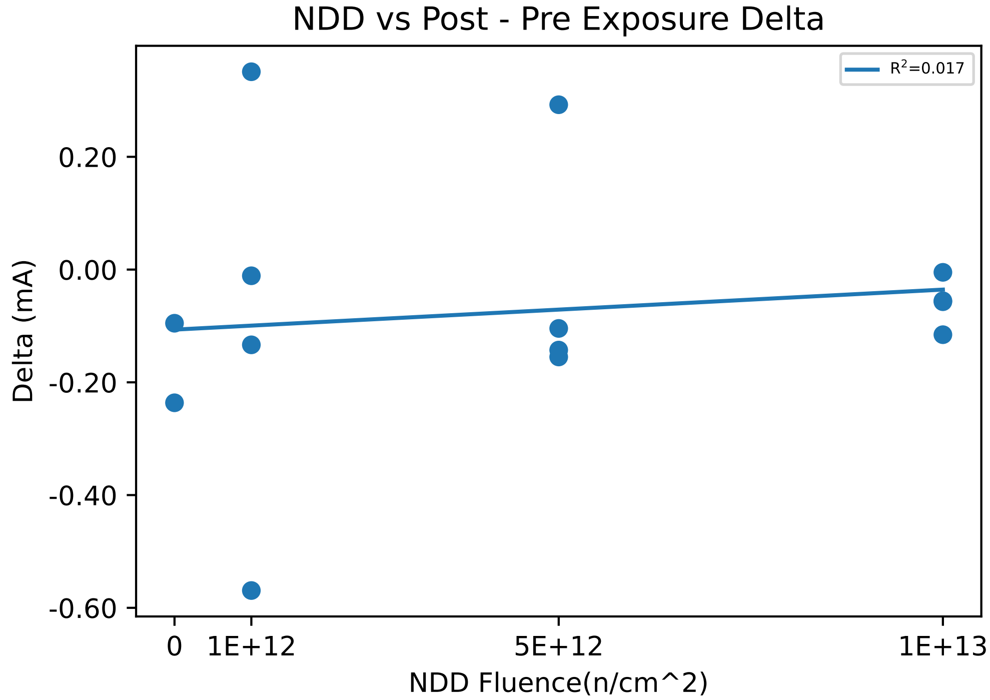
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	7.182	7.2631	7.3443	0.11476	7.2966	7.2979	7.2991	0.0017678	-0.0452	0.0347	0.1146	0.113
1e+12	7.1929	7.2298	7.2886	0.045569	7.1385	7.18	7.2738	0.063471	-0.1044	-0.049775	-0.0148	0.039273
5e+12	7.2126	7.2639	7.3472	0.061994	7.1632	7.1867	7.2414	0.036733	-0.1058	-0.0772	-0.0494	0.030239
1e+13	7.1211	7.1812	7.2697	0.067141	7.1151	7.1554	7.2497	0.063423	-0.0611	-0.0258	0.0008	0.025792

Device Test: 35.12 I_OP_LS_PWM_5MHZ(_Iop LS VIN PWM 5MHz VIN_10V)



Test Results (Upper Limit = 30.0 (mA))

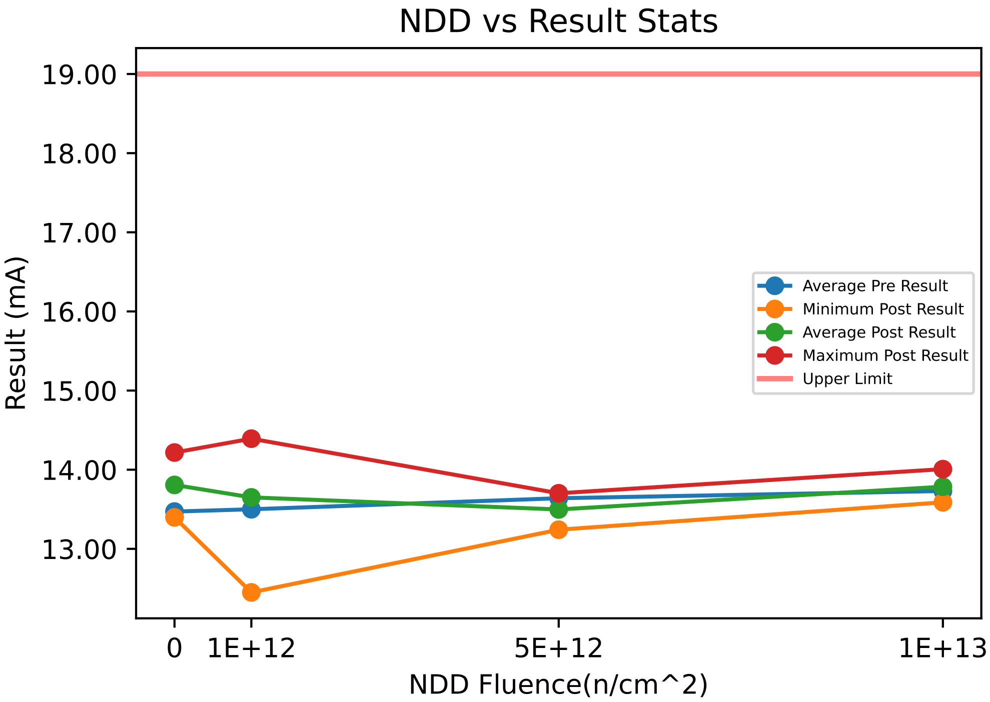
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	17.288	17.052	-0.2363
2	0	Correlation	17.217	17.121	-0.0952
30	1e+12	NDD unbiased	17.677	17.107	-0.5693
31	1e+12	NDD unbiased	17.205	17.556	0.3509
32	1e+12	NDD unbiased	17.302	17.168	-0.1335
33	1e+12	NDD unbiased	16.617	16.606	-0.011
44	5e+12	NDD unbiased	16.711	16.606	-0.1044
45	5e+12	NDD unbiased	16.998	17.29	0.2924
46	5e+12	NDD unbiased	16.97	16.827	-0.1428
47	5e+12	NDD unbiased	17.446	17.291	-0.155
50	1e+13	NDD unbiased	16.804	16.748	-0.0554
51	1e+13	NDD unbiased	17.592	17.477	-0.1155
52	1e+13	NDD unbiased	17.311	17.306	-0.0049
53	1e+13	NDD unbiased	17.172	17.115	-0.057

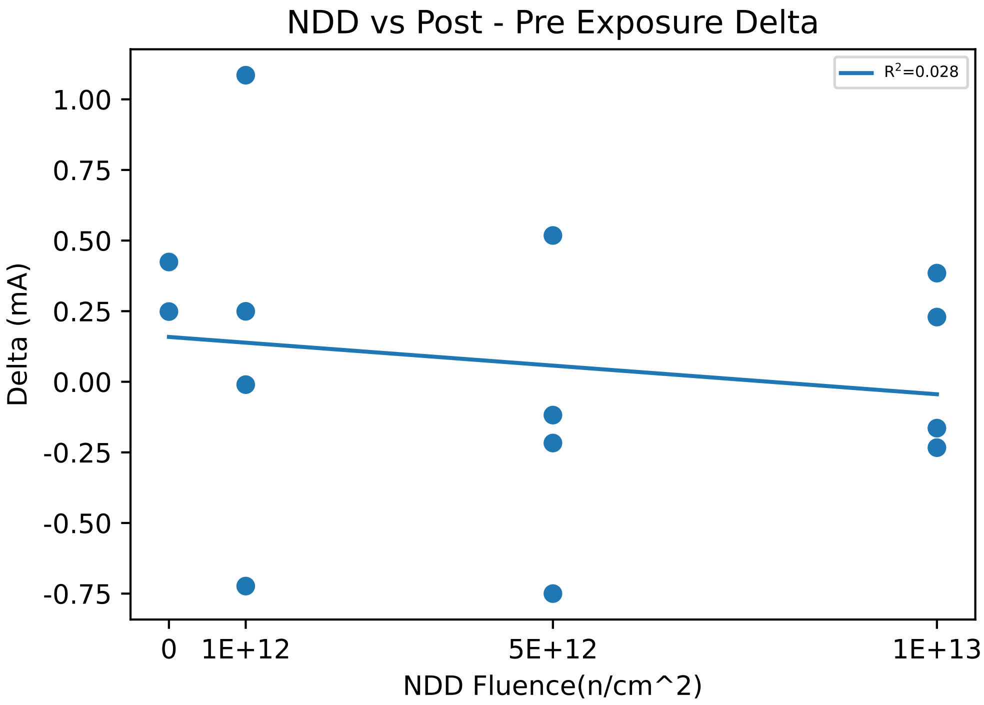


Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	17.217	17.252	17.288	0.050558	17.052	17.087	17.121	0.049215	-0.2363	-0.16575	-0.0952	0.099773
1e+12	16.617	17.2	17.677	0.43872	16.606	17.109	17.556	0.38994	-0.5693	-0.090725	0.3509	0.37958
5e+12	16.711	17.031	17.446	0.30513	16.606	17.004	17.291	0.34335	-0.155	-0.02745	0.2924	0.21432
1e+13	16.804	17.22	17.592	0.32785	16.748	17.162	17.477	0.31264	-0.1155	-0.0582	-0.0049	0.045216

Device Test: 35.13 I_OP_HS_PWM_5MHZ(_Iop HS BOOT PWM 5MHz VIN_10V)





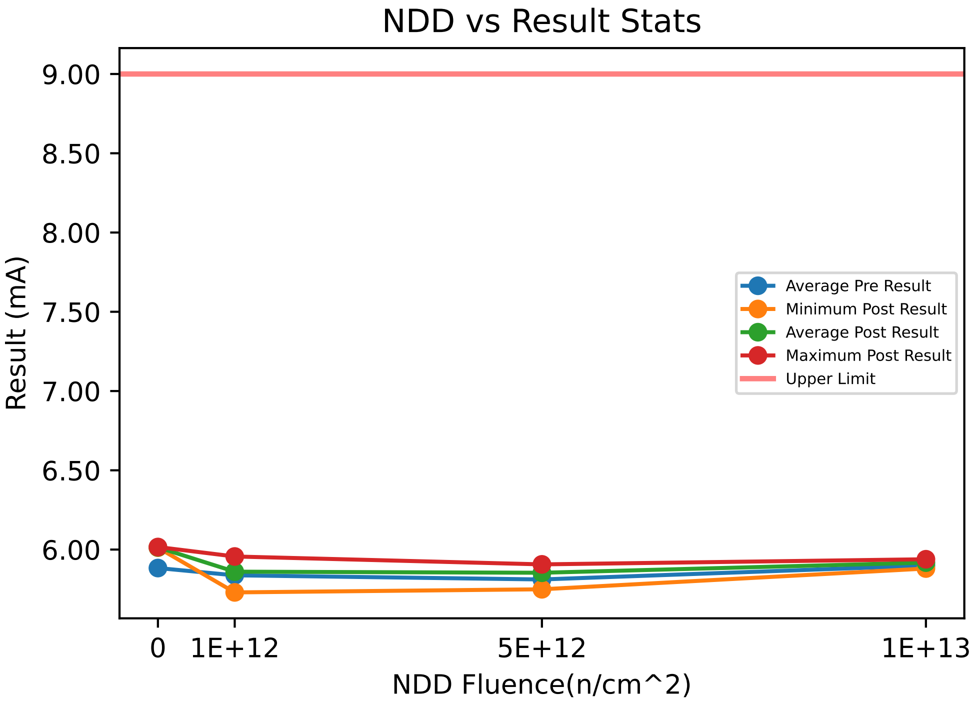
Test Results (Upper Limit = 19.0 (mA))

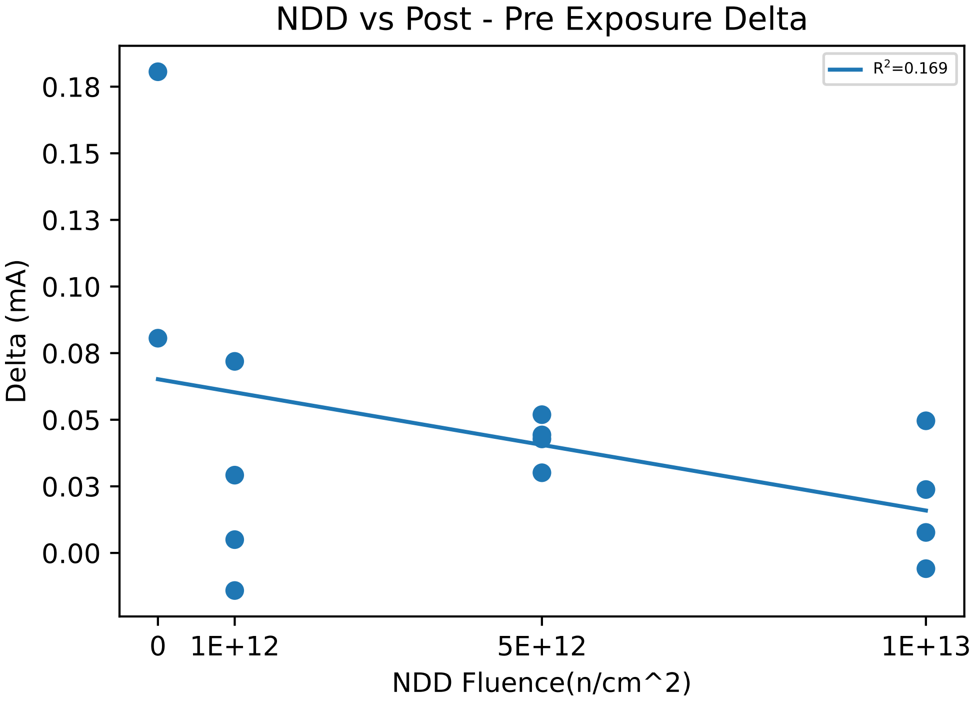
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	13.149	13.398	0.2486
2	0	Correlation	13.793	14.217	0.4241
30	1e+12	NDD unbiased	13.111	14.197	1.0855
31	1e+12	NDD unbiased	14.287	13.563	-0.7234
32	1e+12	NDD unbiased	12.2	12.45	0.2494
33	1e+12	NDD unbiased	14.402	14.392	-0.0101
44	5e+12	NDD unbiased	13.861	13.645	-0.2169
45	5e+12	NDD unbiased	13.992	13.242	-0.75
46	5e+12	NDD unbiased	13.82	13.702	-0.118
47	5e+12	NDD unbiased	12.884	13.402	0.518
50	1e+13	NDD unbiased	14.241	14.007	-0.2333
51	1e+13	NDD unbiased	13.233	13.617	0.3847
52	1e+13	NDD unbiased	13.698	13.927	0.2291
53	1e+13	NDD unbiased	13.752	13.588	-0.1641

Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	13.149	13.471	13.793	0.45502	13.398	13.808	14.217	0.57912	0.2486	0.33635	0.4241	0.1241
1e+12	12.2	13.5	14.402	1.0446	12.45	13.65	14.392	0.87514	-0.7234	0.15035	1.0855	0.74688
5e+12	12.884	13.639	13.992	0.50894	13.242	13.498	13.702	0.21448	-0.75	-0.14173	0.518	0.52008
1e+13	13.233	13.731	14.241	0.41205	13.588	13.785	14.007	0.21318	-0.2333	0.0541	0.3847	0.30007

Device Test: 35.14 I_OP_LS_IIM_500KHZ(_Iop LS VIN IIM Interlock 500kHz VIN_10V)


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

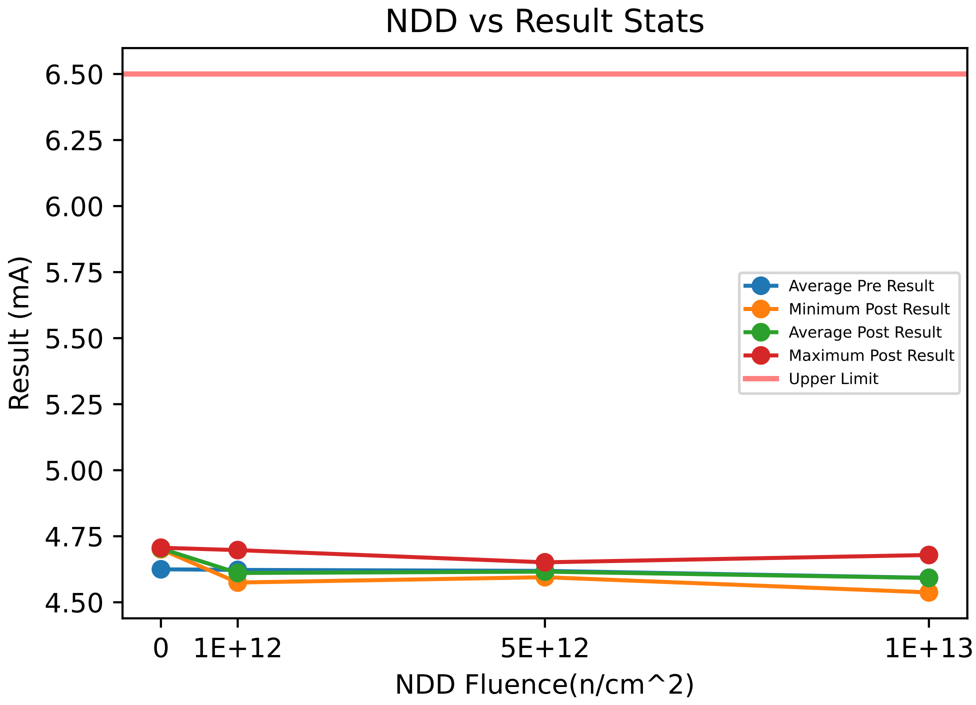
Test Results (Upper Limit = 9.0 (mA))

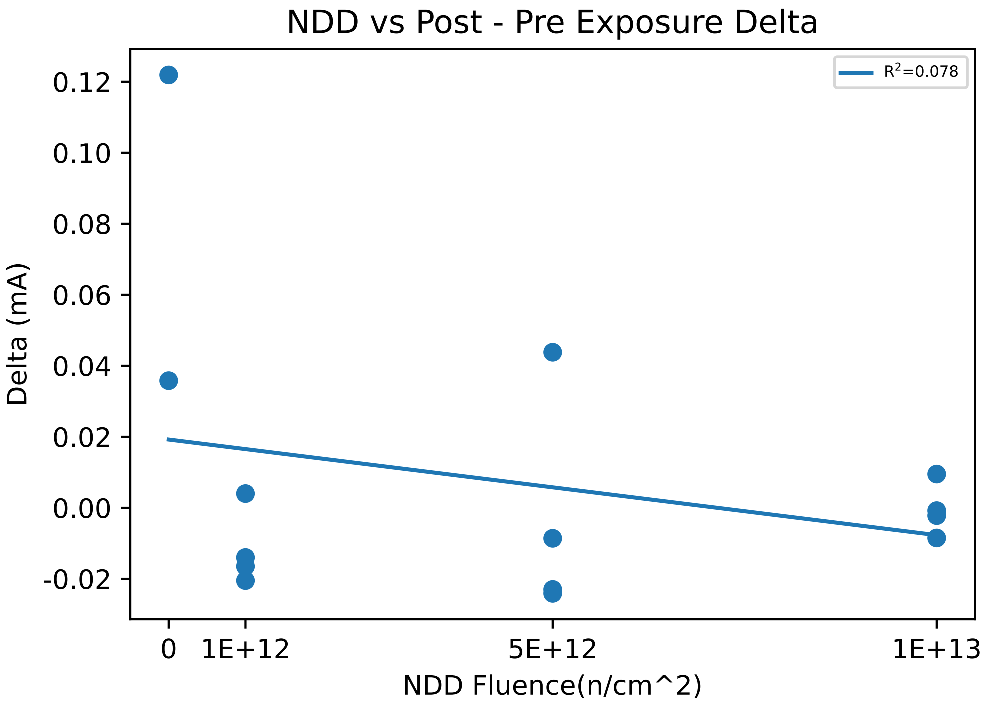
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	5.8355	6.0161	0.1806
2	0	Correlation	5.9314	6.012	0.0806
30	1e+12	NDD unbiased	5.9277	5.9136	-0.0141
31	1e+12	NDD unbiased	5.8844	5.9563	0.0719
32	1e+12	NDD unbiased	5.8134	5.8426	0.0292
33	1e+12	NDD unbiased	5.7248	5.7298	0.005
44	5e+12	NDD unbiased	5.7051	5.7494	0.0443
45	5e+12	NDD unbiased	5.8521	5.904	0.0519
46	5e+12	NDD unbiased	5.812	5.8548	0.0428
47	5e+12	NDD unbiased	5.8765	5.9066	0.0301
50	1e+13	NDD unbiased	5.9303	5.9244	-0.0059
51	1e+13	NDD unbiased	5.8772	5.9268	0.0496
52	1e+13	NDD unbiased	5.8565	5.8803	0.0238
53	1e+13	NDD unbiased	5.9312	5.9389	0.0077

Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.8355	5.8834	5.9314	0.067812	6.012	6.014	6.0161	0.0028991	0.0806	0.1306	0.1806	0.070711
1e+12	5.7248	5.8376	5.9277	0.088728	5.7298	5.8606	5.9563	0.098995	-0.0141	0.023	0.0719	0.037104
5e+12	5.7051	5.8114	5.8765	0.075707	5.7494	5.8537	5.9066	0.073503	0.0301	0.042275	0.0519	0.0090415
1e+13	5.8565	5.8988	5.9312	0.03785	5.8803	5.9176	5.9389	0.025664	-0.0059	0.0188	0.0496	0.023853

Device Test: 35.15 I_OP_HS_IIM_500KHZ(_Iop HS BOOT IIM Interlock 500kHz VIN_10V)





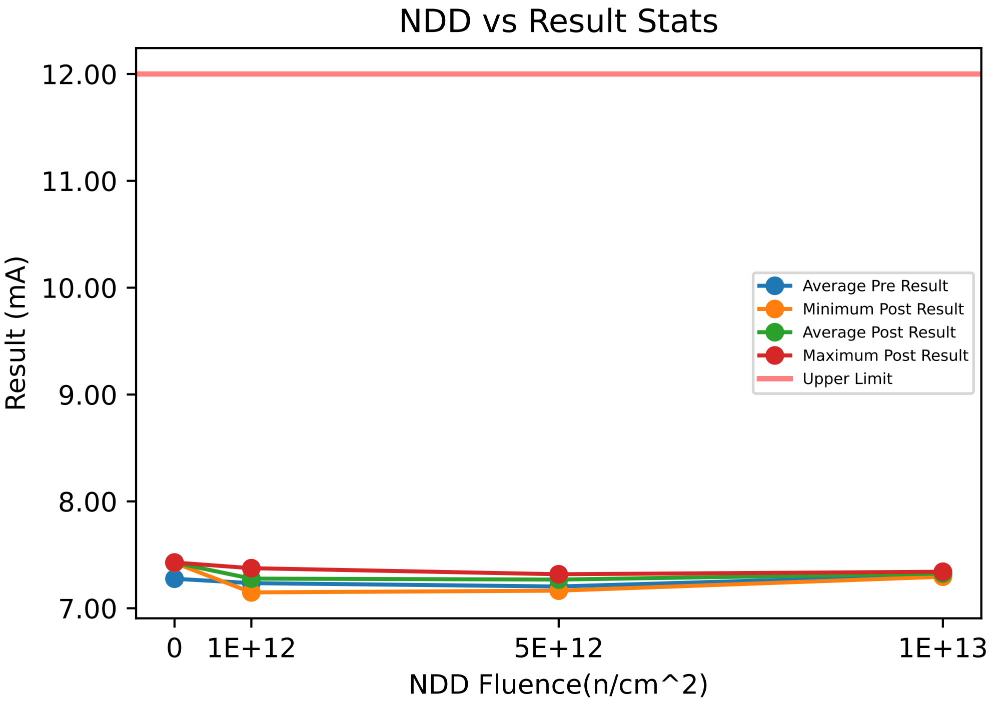
Test Results (Upper Limit = 6.5 (mA))

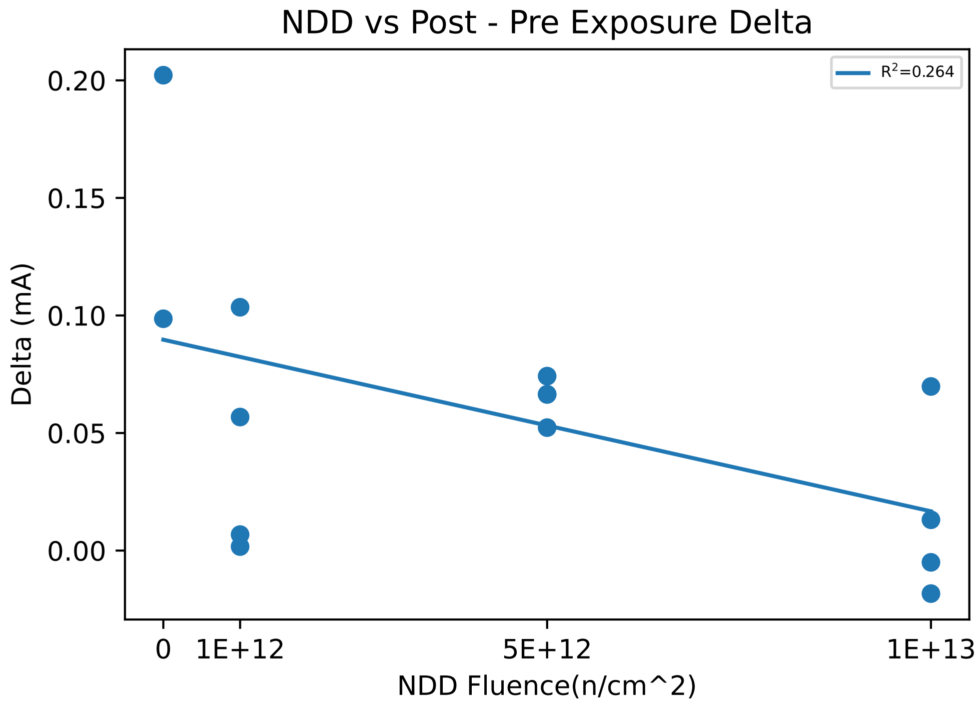
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	4.5846	4.7065	0.1219
2	0	Correlation	4.6651	4.7009	0.0358
30	1e+12	NDD unbiased	4.5975	4.581	-0.0165
31	1e+12	NDD unbiased	4.5952	4.5747	-0.0205
32	1e+12	NDD unbiased	4.6043	4.5903	-0.014
33	1e+12	NDD unbiased	4.6935	4.6975	0.004
44	5e+12	NDD unbiased	4.6754	4.6513	-0.0241
45	5e+12	NDD unbiased	4.5634	4.6072	0.0438
46	5e+12	NDD unbiased	4.6179	4.5949	-0.023
47	5e+12	NDD unbiased	4.619	4.6104	-0.0086
50	1e+13	NDD unbiased	4.5382	4.5374	-0.0008
51	1e+13	NDD unbiased	4.6032	4.5947	-0.0085
52	1e+13	NDD unbiased	4.5476	4.5571	0.0095
53	1e+13	NDD unbiased	4.6812	4.679	-0.0022

Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.5846	4.6249	4.6651	0.056922	4.7009	4.7037	4.7065	0.0039598	0.0358	0.07885	0.1219	0.060882
1e+12	4.5952	4.6226	4.6935	0.047408	4.5747	4.6109	4.6975	0.058104	-0.0205	-0.01175	0.004	0.010836
5e+12	4.5634	4.6189	4.6754	0.045729	4.5949	4.6159	4.6513	0.024496	-0.0241	-0.002975	0.0438	0.031973
1e+13	4.5382	4.5926	4.6812	0.065693	4.5374	4.5921	4.679	0.062651	-0.0085	-0.0005	0.0095	0.0074606

Device Test: 35.16 I_OP_LS_IIM_1MHZ(_Iop LS VIN IIM Interlock 1MHz VIN_10V)





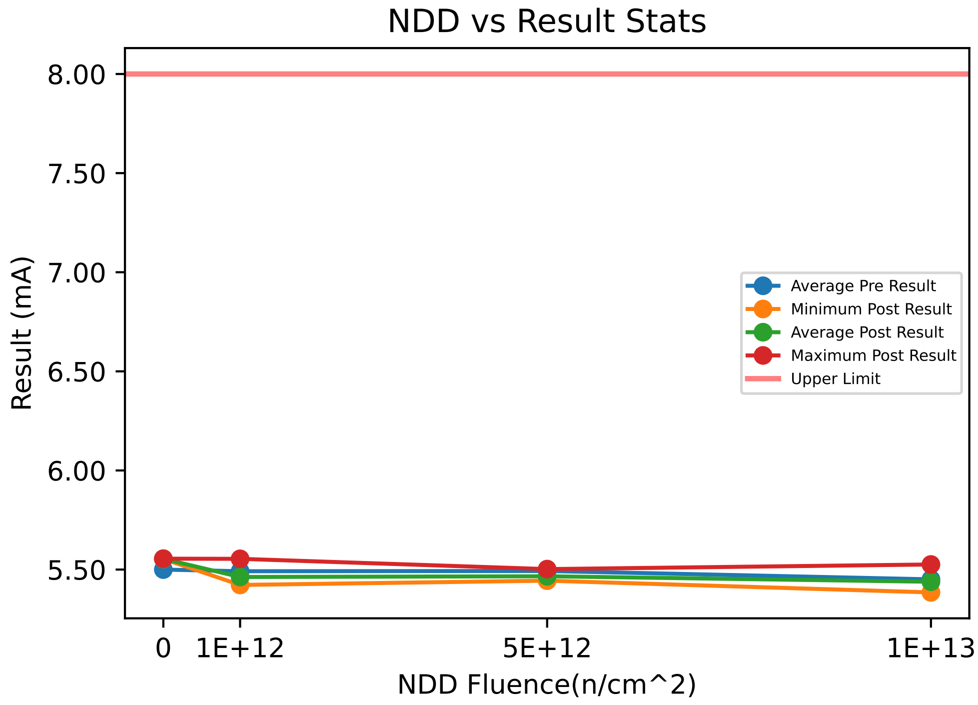
Test Results (Upper Limit = 12.0 (mA))

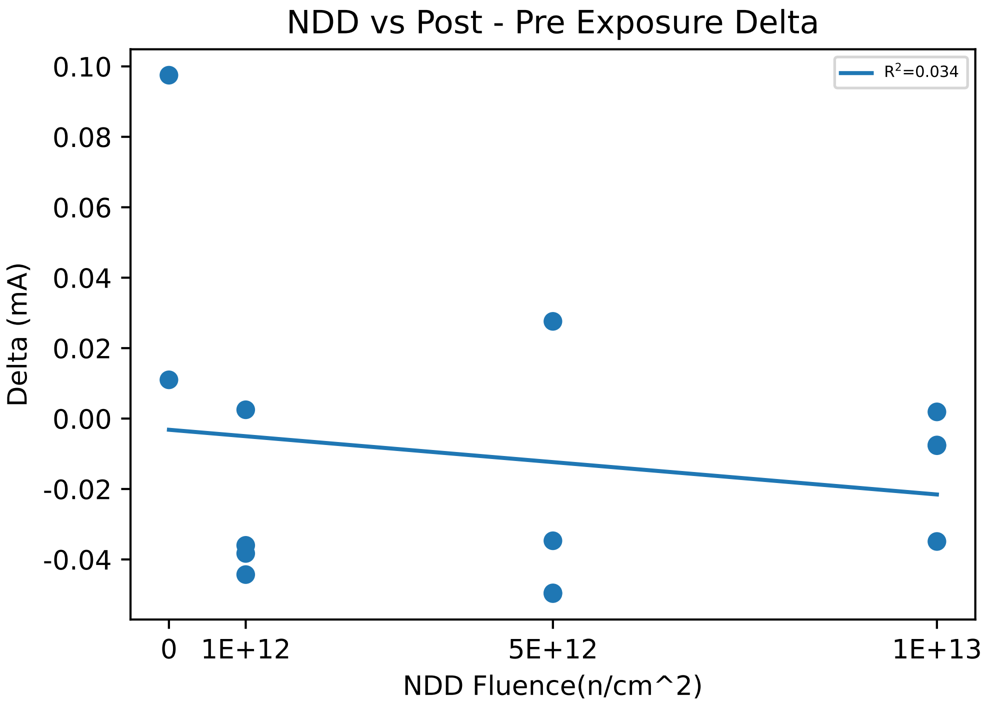
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	7.2259	7.4281	0.2022
2	0	Correlation	7.3262	7.4248	0.0986
30	1e+12	NDD unbiased	7.32	7.3268	0.0068
31	1e+12	NDD unbiased	7.2714	7.3749	0.1035
32	1e+12	NDD unbiased	7.2024	7.2592	0.0568
33	1e+12	NDD unbiased	7.1466	7.1483	0.0017
44	5e+12	NDD unbiased	7.0981	7.1645	0.0664
45	5e+12	NDD unbiased	7.2431	7.3173	0.0742
46	5e+12	NDD unbiased	7.207	7.2735	0.0665
47	5e+12	NDD unbiased	7.2659	7.3182	0.0523
50	1e+13	NDD unbiased	7.3496	7.3313	-0.0183
51	1e+13	NDD unbiased	7.261	7.3308	0.0698
52	1e+13	NDD unbiased	7.2819	7.295	0.0131
53	1e+13	NDD unbiased	7.3466	7.3416	-0.005

Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	7.2259	7.276	7.3262	0.070923	7.4248	7.4264	7.4281	0.0023335	0.0986	0.1504	0.2022	0.073256
1e+12	7.1466	7.2351	7.32	0.076217	7.1483	7.2773	7.3749	0.098225	0.0017	0.0422	0.1035	0.047834
5e+12	7.0981	7.2035	7.2659	0.074349	7.1645	7.2684	7.3182	0.072324	0.0523	0.06485	0.0742	0.0091296
1e+13	7.261	7.3098	7.3496	0.045086	7.295	7.3247	7.3416	0.0204	-0.0183	0.0149	0.0698	0.038796

Device Test: 35.17 I_OP_HS_IIM_1MHZ(_Iop HS BOOT IIM Interlock 1MHz VIN_10V)





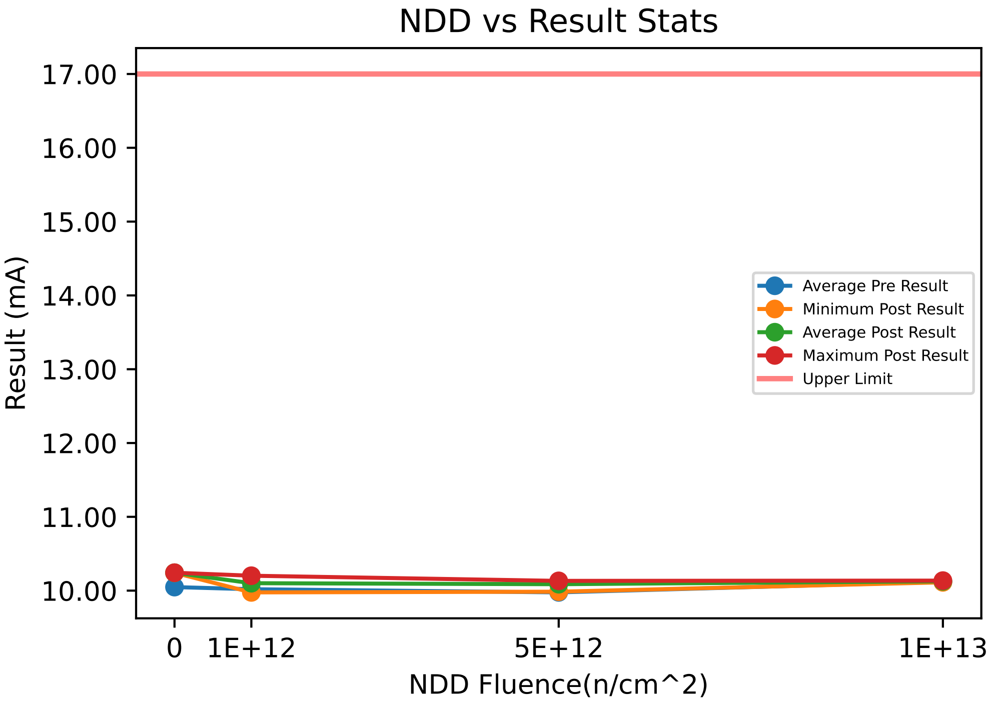
Test Results (Upper Limit = 8.0 (mA))

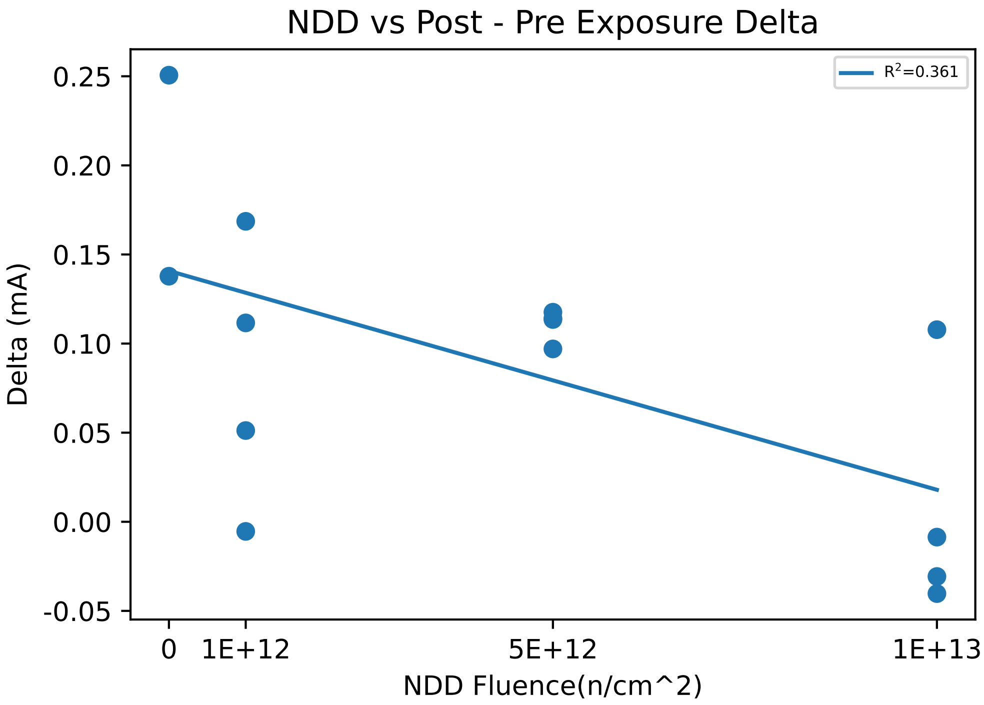
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	5.456	5.5535	0.0975
2	0	Correlation	5.5439	5.5549	0.011
30	1e+12	NDD unbiased	5.4676	5.4293	-0.0383
31	1e+12	NDD unbiased	5.4667	5.4224	-0.0443
32	1e+12	NDD unbiased	5.4803	5.4443	-0.036
33	1e+12	NDD unbiased	5.5516	5.5541	0.0025
44	5e+12	NDD unbiased	5.5518	5.5023	-0.0495
45	5e+12	NDD unbiased	5.431	5.4586	0.0276
46	5e+12	NDD unbiased	5.4937	5.444	-0.0497
47	5e+12	NDD unbiased	5.4946	5.4599	-0.0347
50	1e+13	NDD unbiased	5.3925	5.3848	-0.0077
51	1e+13	NDD unbiased	5.4735	5.4386	-0.0349
52	1e+13	NDD unbiased	5.4034	5.4053	0.0019
53	1e+13	NDD unbiased	5.5331	5.5256	-0.0075

Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.456	5.5	5.5439	0.062155	5.5535	5.5542	5.5549	0.00098995	0.011	0.05425	0.0975	0.061165
1e+12	5.4667	5.4916	5.5516	0.040512	5.4224	5.4625	5.5541	0.061731	-0.0443	-0.029025	0.0025	0.021306
5e+12	5.431	5.4928	5.5518	0.049343	5.444	5.4662	5.5023	0.025123	-0.0497	-0.026575	0.0276	0.036793
1e+13	5.3925	5.4506	5.5331	0.065661	5.3848	5.4386	5.5256	0.062108	-0.0349	-0.01205	0.0019	0.015878

Device Test: 35.18 I_OP_LS_IIM_2MHZ(_Iop LS VIN IIM Interlock 2MHz VIN_10V)





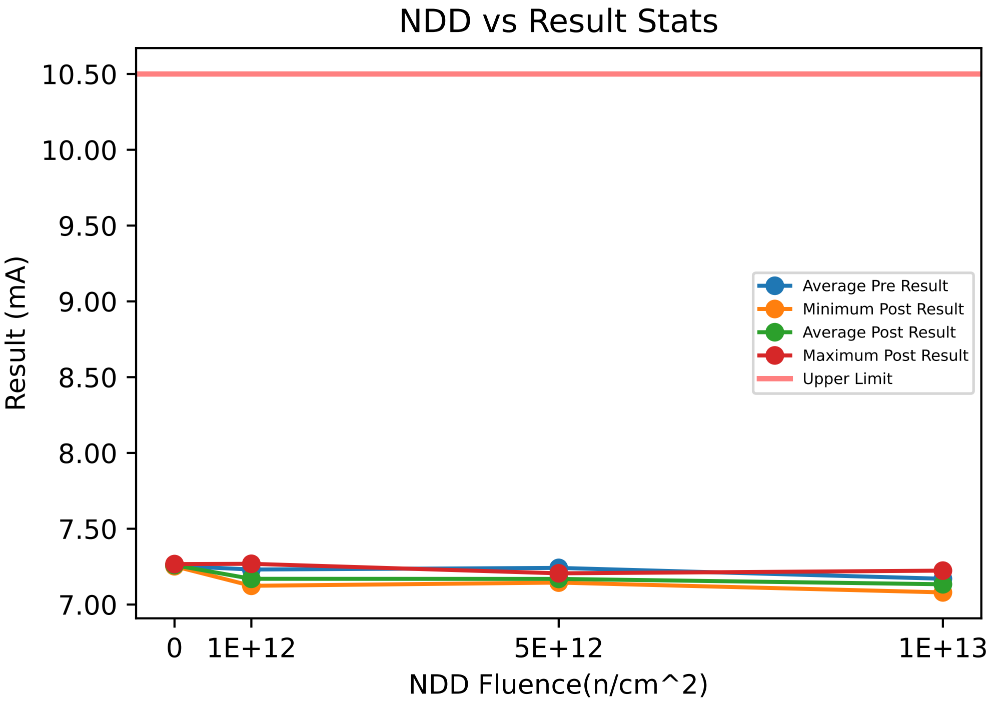
Test Results (Upper Limit = 17.0 (mA))

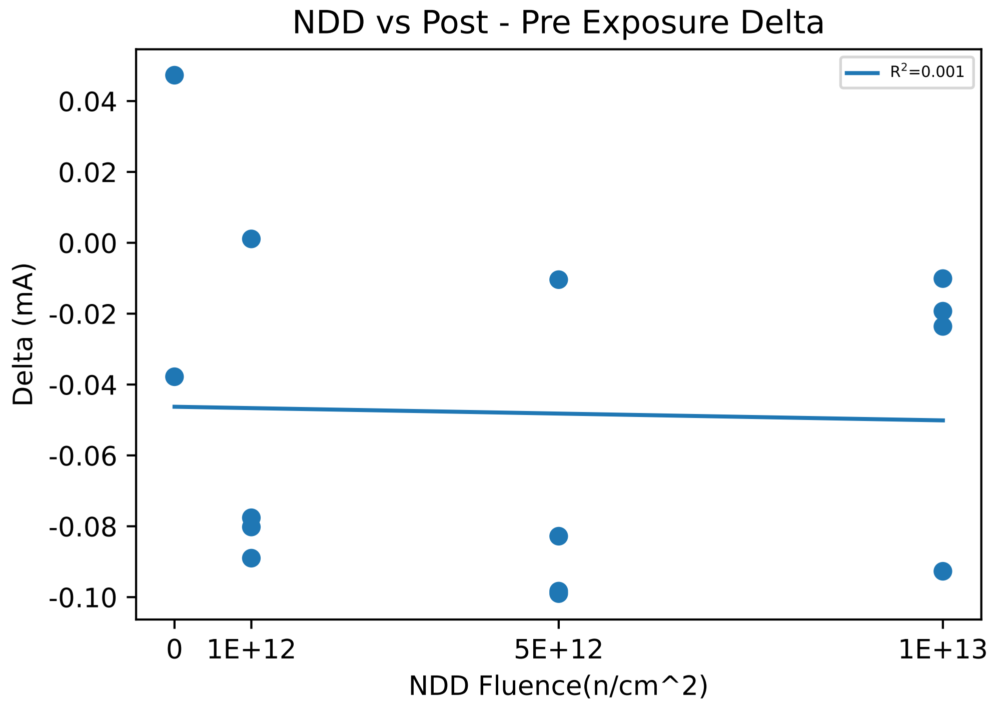
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	9.9922	10.243	0.2506
2	0	Correlation	10.104	10.242	0.1378
30	1e+12	NDD unbiased	10.092	10.143	0.0512
31	1e+12	NDD unbiased	10.034	10.202	0.1686
32	1e+12	NDD unbiased	9.9696	10.081	0.1116
33	1e+12	NDD unbiased	9.9815	9.9761	-0.0054
44	5e+12	NDD unbiased	9.8715	9.9857	0.1142
45	5e+12	NDD unbiased	10.013	10.131	0.1176
46	5e+12	NDD unbiased	9.9858	10.099	0.1135
47	5e+12	NDD unbiased	10.035	10.132	0.097
50	1e+13	NDD unbiased	10.174	10.134	-0.0403
51	1e+13	NDD unbiased	10.017	10.124	0.1078
52	1e+13	NDD unbiased	10.121	10.113	-0.0086
53	1e+13	NDD unbiased	10.166	10.136	-0.0307

Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	9.9922	10.048	10.104	0.078984	10.242	10.242	10.243	0.00077782	0.1378	0.1942	0.2506	0.079762
1e+12	9.9696	10.019	10.092	0.056021	9.9761	10.101	10.202	0.096628	-0.0054	0.0815	0.1686	0.075193
5e+12	9.8715	9.9764	10.035	0.072837	9.9857	10.087	10.132	0.069242	0.097	0.11058	0.1176	0.0092255
1e+13	10.017	10.12	10.174	0.072601	10.113	10.127	10.136	0.010678	-0.0403	0.00705	0.1078	0.068465

Device Test: 35.19 I_OP_HS_IIM_2MHZ(_Iop HS BOOT IIM Interlock 2MHz VIN_10V)





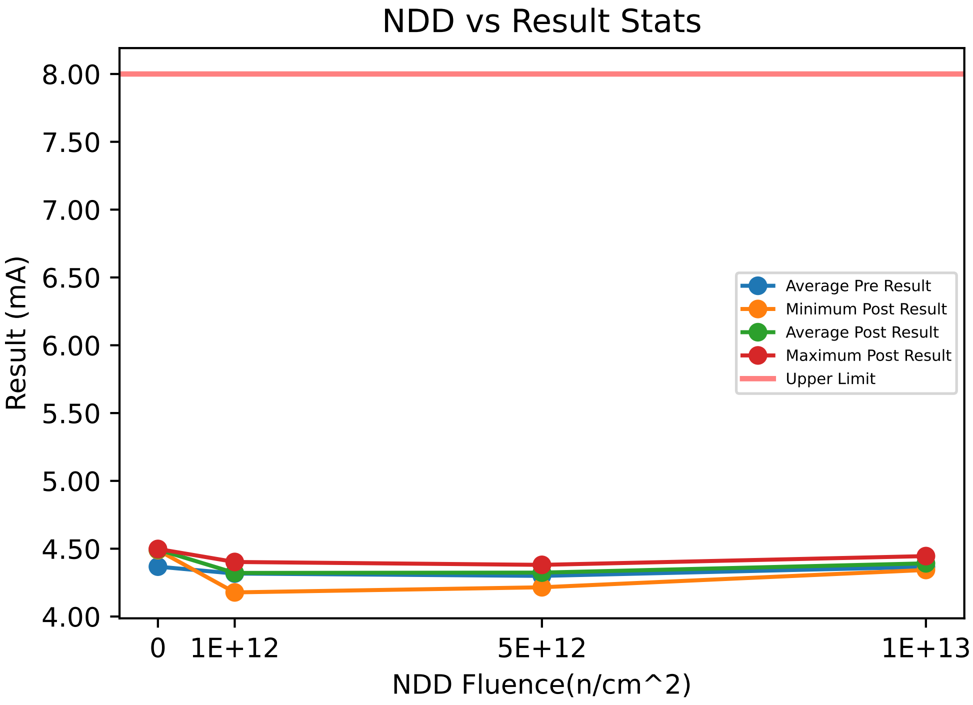
Test Results (Upper Limit = 10.5 (mA))

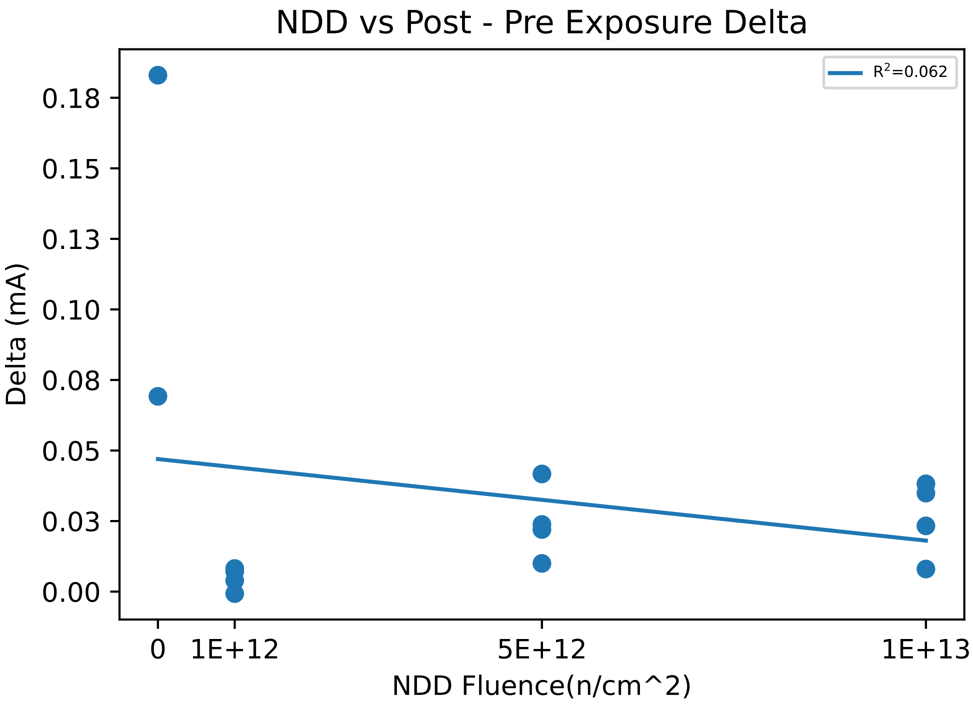
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	7.2052	7.2525	0.0473
2	0	Correlation	7.3047	7.2669	-0.0378
30	1e+12	NDD unbiased	7.2118	7.1316	-0.0802
31	1e+12	NDD unbiased	7.2126	7.1236	-0.089
32	1e+12	NDD unbiased	7.2326	7.155	-0.0776
33	1e+12	NDD unbiased	7.2676	7.2687	0.0011
44	5e+12	NDD unbiased	7.3049	7.2059	-0.099
45	5e+12	NDD unbiased	7.1715	7.1611	-0.0104
46	5e+12	NDD unbiased	7.2431	7.1448	-0.0983
47	5e+12	NDD unbiased	7.2474	7.1646	-0.0828
50	1e+13	NDD unbiased	7.1037	7.0801	-0.0236
51	1e+13	NDD unbiased	7.2201	7.1274	-0.0927
52	1e+13	NDD unbiased	7.1138	7.1037	-0.0101
53	1e+13	NDD unbiased	7.2429	7.2236	-0.0193

Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	7.2052	7.255	7.3047	0.070357	7.2525	7.2597	7.2669	0.010182	-0.0378	0.00475	0.0473	0.060175
1e+12	7.2118	7.2311	7.2676	0.026136	7.1236	7.1697	7.2687	0.067315	-0.089	-0.061425	0.0011	0.041968
5e+12	7.1715	7.2417	7.3049	0.05464	7.1448	7.1691	7.2059	0.026006	-0.099	-0.072625	-0.0104	0.042152
1e+13	7.1037	7.1701	7.2429	0.071597	7.0801	7.1337	7.2236	0.062967	-0.0927	-0.036425	-0.0101	0.037937

Device Test: 35.2 IQ_LS_IIM(_Iq LS VIN IIM Interlock VIN_10V)


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

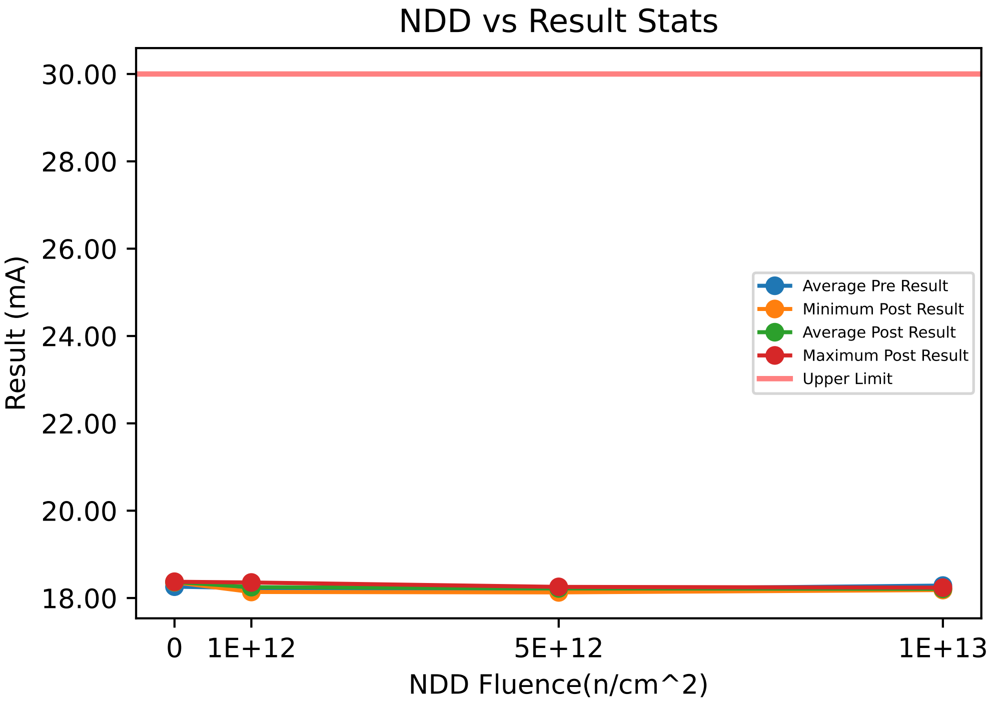
Test Results (Upper Limit = 8.0 (mA))

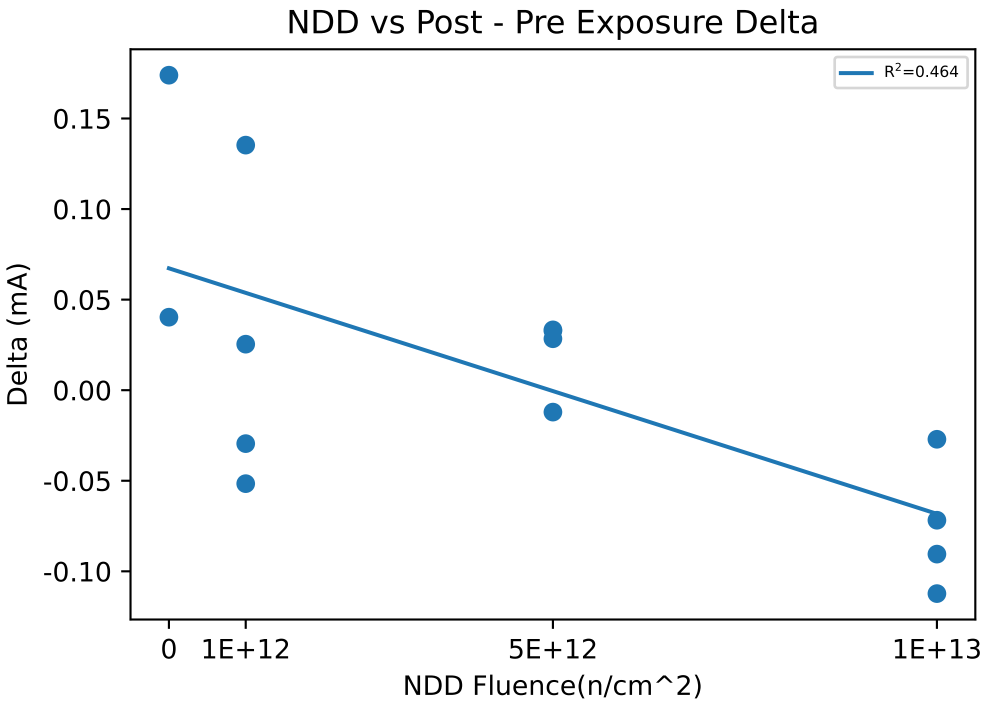
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	4.3152	4.4982	0.183
2	0	Correlation	4.4201	4.4893	0.0692
30	1e+12	NDD unbiased	4.3949	4.4021	0.0072
31	1e+12	NDD unbiased	4.3979	4.3972	-0.0007
32	1e+12	NDD unbiased	4.3046	4.3085	0.0039
33	1e+12	NDD unbiased	4.1696	4.1778	0.0082
44	5e+12	NDD unbiased	4.1917	4.2155	0.0238
45	5e+12	NDD unbiased	4.3372	4.3789	0.0417
46	5e+12	NDD unbiased	4.2979	4.3199	0.022
47	5e+12	NDD unbiased	4.3708	4.3808	0.01
50	1e+13	NDD unbiased	4.3731	4.3811	0.008
51	1e+13	NDD unbiased	4.4105	4.4454	0.0349
52	1e+13	NDD unbiased	4.305	4.3432	0.0382
53	1e+13	NDD unbiased	4.3749	4.3982	0.0233

Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.3152	4.3676	4.4201	0.074176	4.4893	4.4938	4.4982	0.0062933	0.0692	0.1261	0.183	0.080469
1e+12	4.1696	4.3167	4.3979	0.10723	4.1778	4.3214	4.4021	0.10495	-0.0007	0.00465	0.0082	0.0040121
5e+12	4.1917	4.2994	4.3708	0.077735	4.2155	4.3238	4.3808	0.077522	0.01	0.024375	0.0417	0.013074
1e+13	4.305	4.3659	4.4105	0.044086	4.3432	4.392	4.4454	0.042388	0.008	0.0261	0.0382	0.013654

Device Test: 35.20 I_OP_LS_IIM_5MHZ(_Iop LS VIN IIM Interlock 5MHz VIN_10V)





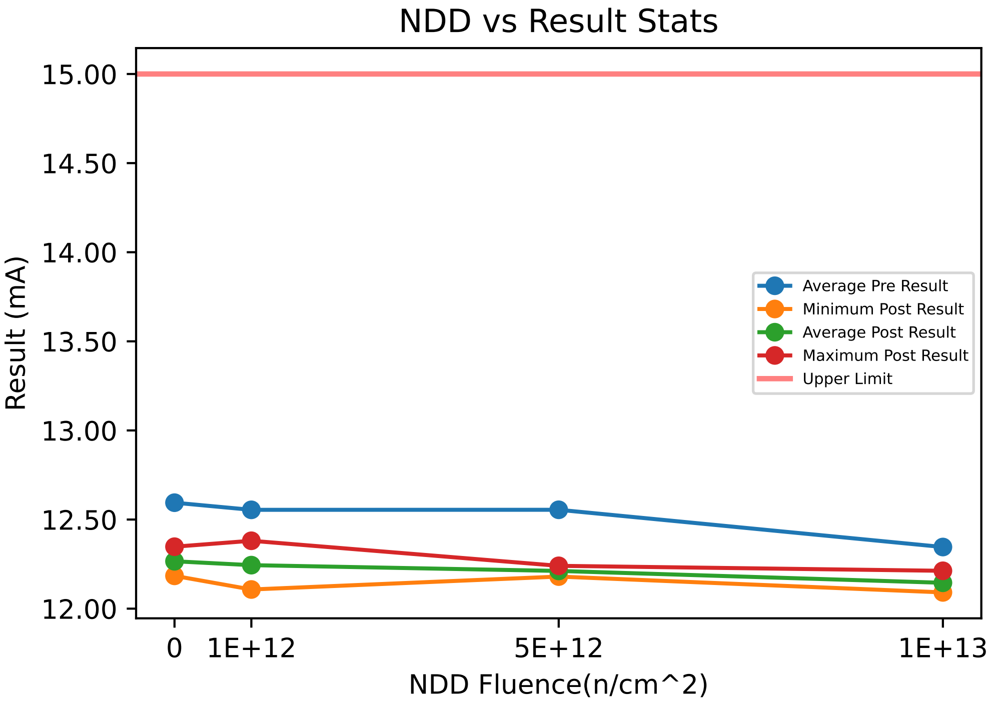
Test Results (Upper Limit = 30.0 (mA))

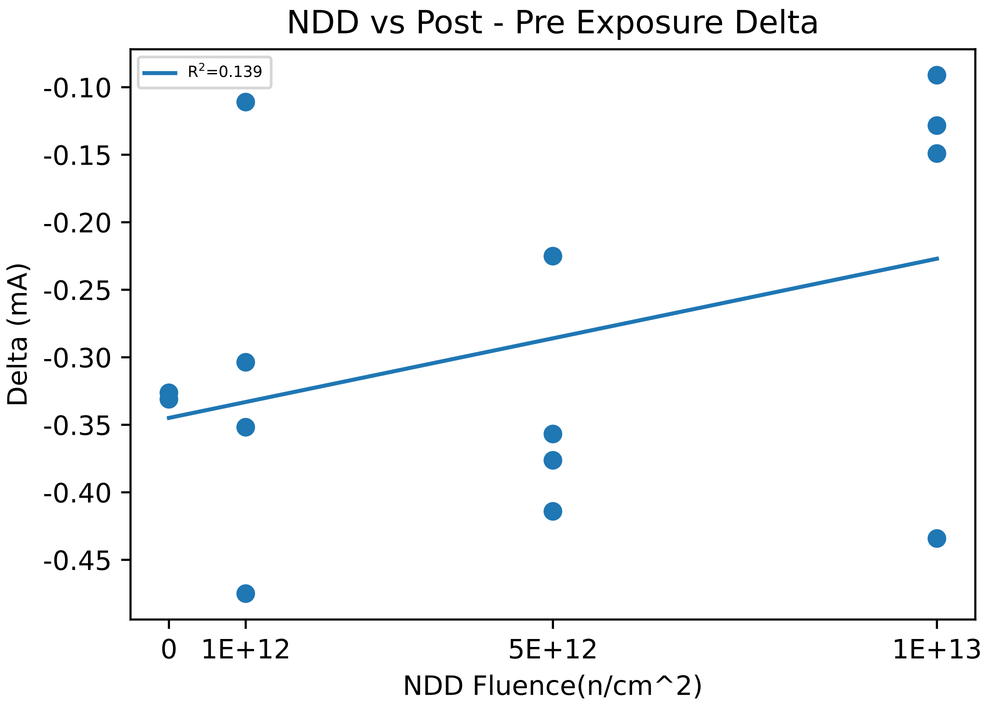
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	18.187	18.361	0.1739
2	0	Correlation	18.333	18.373	0.0403
30	1e+12	NDD unbiased	18.326	18.274	-0.0516
31	1e+12	NDD unbiased	18.221	18.356	0.1353
32	1e+12	NDD unbiased	18.202	18.227	0.0254
33	1e+12	NDD unbiased	18.168	18.138	-0.0295
44	5e+12	NDD unbiased	18.096	18.129	0.0328
45	5e+12	NDD unbiased	18.213	18.246	0.0333
46	5e+12	NDD unbiased	18.227	18.255	0.0284
47	5e+12	NDD unbiased	18.26	18.248	-0.0121
50	1e+13	NDD unbiased	18.332	18.22	-0.1123
51	1e+13	NDD unbiased	18.209	18.182	-0.0271
52	1e+13	NDD unbiased	18.309	18.238	-0.0718
53	1e+13	NDD unbiased	18.291	18.2	-0.0905

Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	18.187	18.26	18.333	0.10317	18.361	18.367	18.373	0.0086974	0.0403	0.1071	0.1739	0.094469
1e+12	18.168	18.229	18.326	0.068112	18.138	18.249	18.356	0.090914	-0.0516	0.0199	0.1353	0.083467
5e+12	18.096	18.199	18.26	0.071497	18.129	18.22	18.255	0.060671	-0.0121	0.0206	0.0333	0.021911
1e+13	18.209	18.285	18.332	0.053376	18.182	18.21	18.238	0.023964	-0.1123	-0.075425	-0.0271	0.036219

Device Test: 35.21 I_OP_HS_IIM_5MHZ(_Iop HS BOOT IIM Interlock 5MHz VIN_10V)





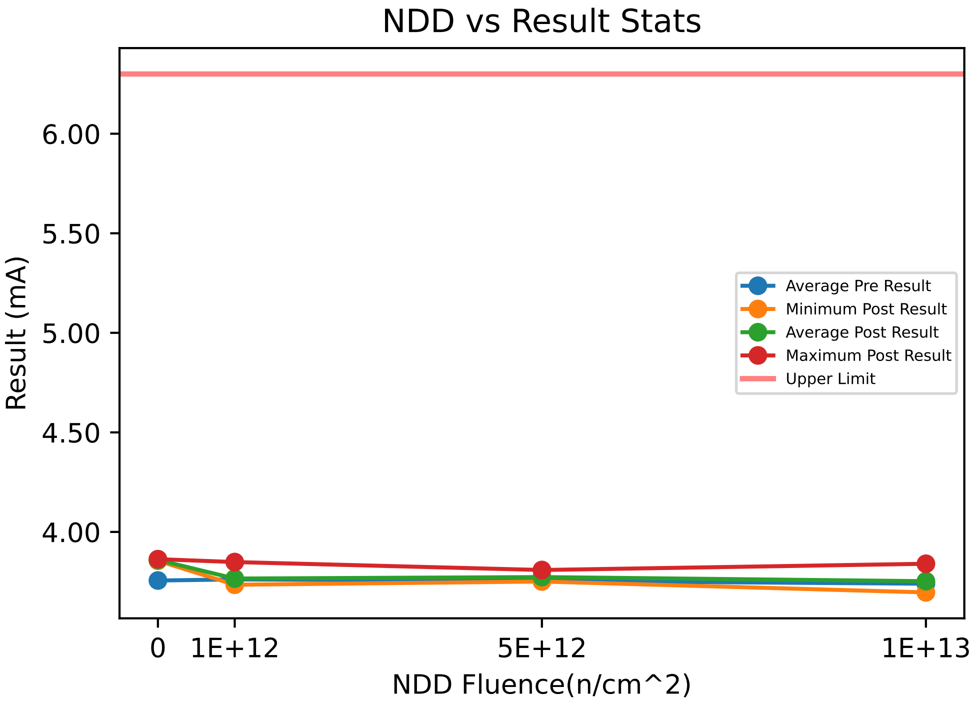
Test Results (Upper Limit = 15.0 (mA))

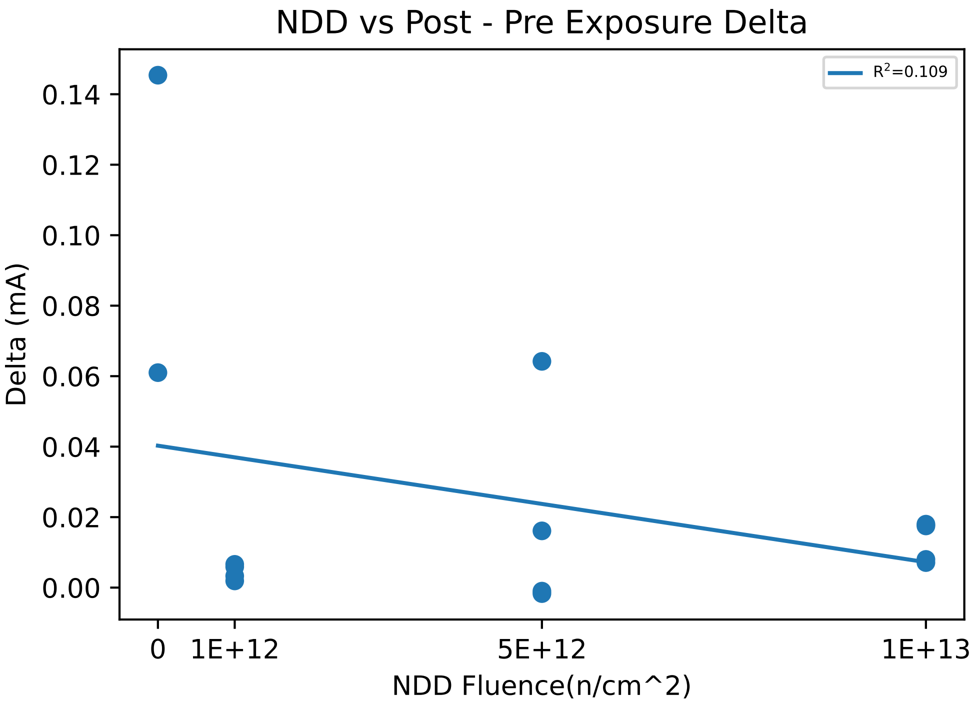
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	12.515	12.184	-0.3311
2	0	Correlation	12.674	12.348	-0.3263
30	1e+12	NDD unbiased	12.503	12.199	-0.3037
31	1e+12	NDD unbiased	12.582	12.107	-0.475
32	1e+12	NDD unbiased	12.64	12.289	-0.3518
33	1e+12	NDD unbiased	12.492	12.381	-0.111
44	5e+12	NDD unbiased	12.594	12.18	-0.4141
45	5e+12	NDD unbiased	12.456	12.231	-0.2251
46	5e+12	NDD unbiased	12.572	12.195	-0.3763
47	5e+12	NDD unbiased	12.597	12.24	-0.3568
50	1e+13	NDD unbiased	12.274	12.125	-0.1491
51	1e+13	NDD unbiased	12.525	12.091	-0.4342
52	1e+13	NDD unbiased	12.28	12.152	-0.1284
53	1e+13	NDD unbiased	12.303	12.212	-0.0911

Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	12.515	12.595	12.674	0.11222	12.184	12.266	12.348	0.11561	-0.3311	-0.3287	-0.3263	0.0033941
1e+12	12.492	12.554	12.64	0.070097	12.107	12.244	12.381	0.11742	-0.475	-0.31037	-0.111	0.15123
5e+12	12.456	12.555	12.597	0.06667	12.18	12.212	12.24	0.028702	-0.4141	-0.34308	-0.2251	0.082168
1e+13	12.274	12.346	12.525	0.12038	12.091	12.145	12.212	0.051215	-0.4342	-0.2007	-0.0911	0.15751

Device Test: 35.3 IQ_HS_IIM(_Iq HS BOOT IIM Interlock VIN_10V)





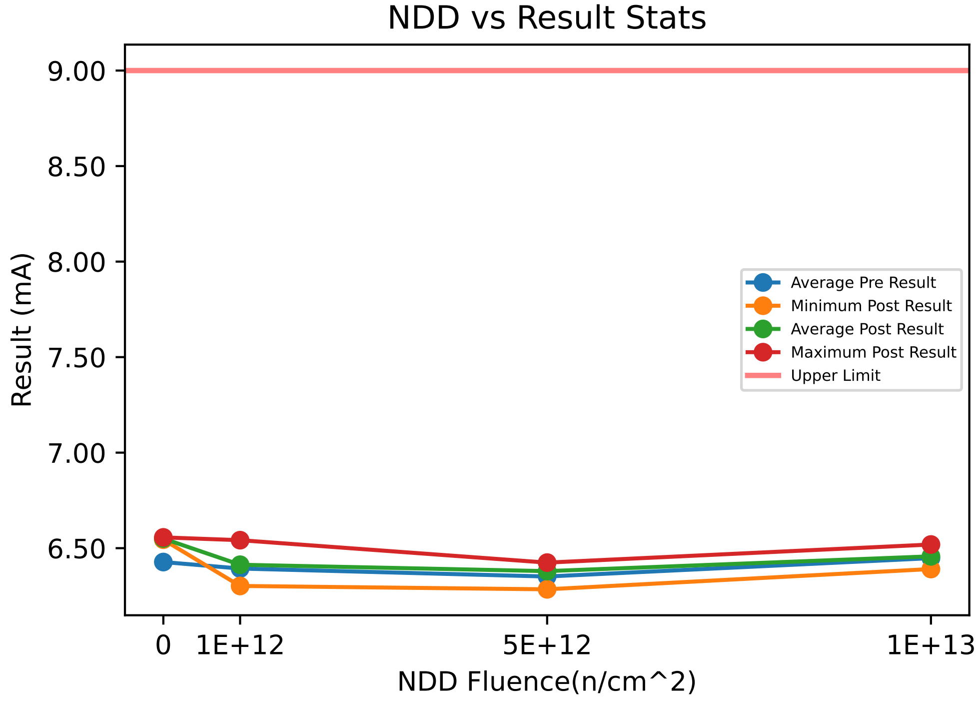
Test Results (Upper Limit = 6.3 (mA))

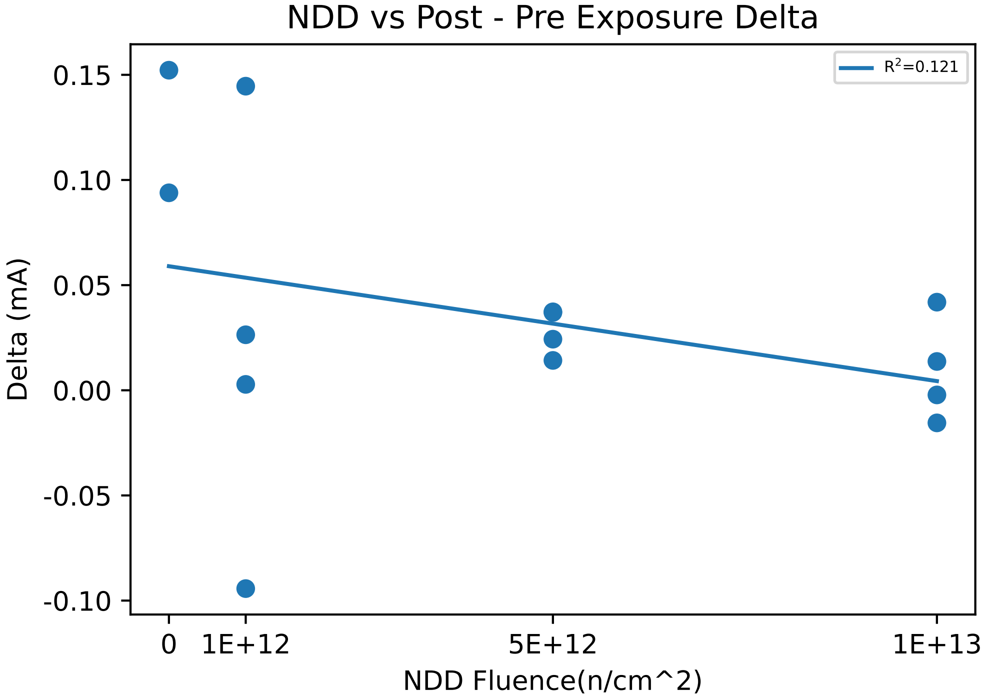
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	3.7179	3.8633	0.1454
2	0	Correlation	3.7942	3.8552	0.061
30	1e+12	NDD unbiased	3.7356	3.7375	0.0019
31	1e+12	NDD unbiased	3.7314	3.7347	0.0033
32	1e+12	NDD unbiased	3.7368	3.7427	0.0059
33	1e+12	NDD unbiased	3.8421	3.8487	0.0066
44	5e+12	NDD unbiased	3.8105	3.8088	-0.0017
45	5e+12	NDD unbiased	3.701	3.7652	0.0642
46	5e+12	NDD unbiased	3.752	3.751	-0.001
47	5e+12	NDD unbiased	3.7519	3.768	0.0161
50	1e+13	NDD unbiased	3.6892	3.6963	0.0071
51	1e+13	NDD unbiased	3.74	3.7575	0.0175
52	1e+13	NDD unbiased	3.6982	3.7162	0.018
53	1e+13	NDD unbiased	3.8321	3.8401	0.008

Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.7179	3.7561	3.7942	0.053952	3.8552	3.8593	3.8633	0.0057276	0.061	0.1032	0.1454	0.05968
1e+12	3.7314	3.7615	3.8421	0.0538	3.7347	3.7659	3.8487	0.055299	0.0019	0.004425	0.0066	0.0022021
5e+12	3.701	3.7538	3.8105	0.044757	3.751	3.7732	3.8088	0.024841	-0.0017	0.0194	0.0642	0.03098
1e+13	3.6892	3.7399	3.8321	0.065346	3.6963	3.7525	3.8401	0.063705	0.0071	0.01265	0.018	0.005904

Device Test: 35.6 I_OP_LS_PWM_500KHZ(_Iop LS VIN PWM 500kHz VIN_10V)





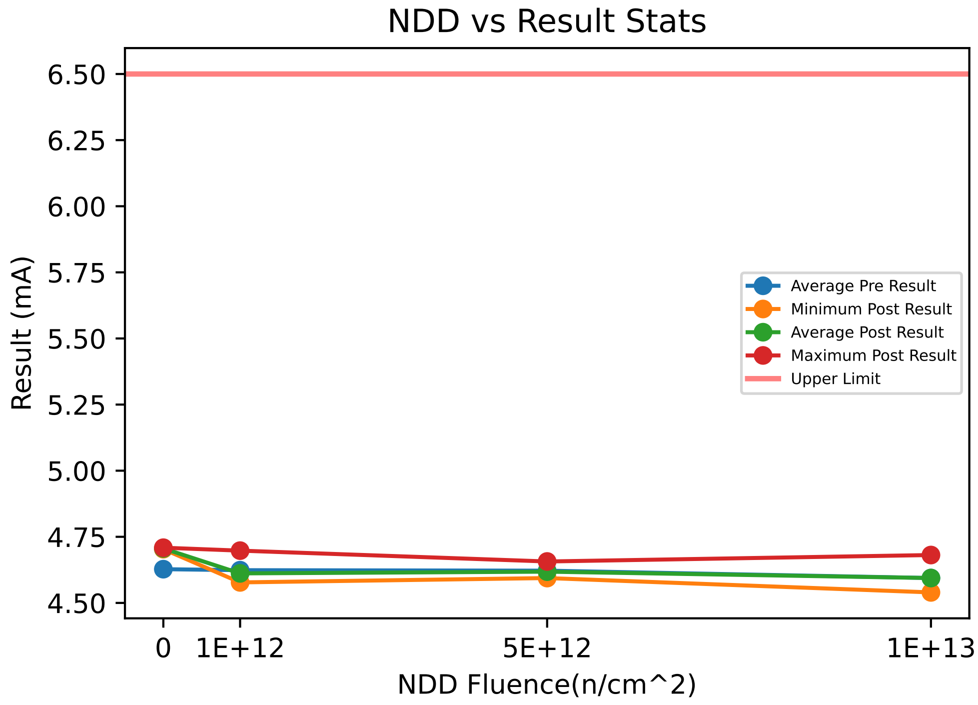
Test Results (Upper Limit = 9.0 (mA))

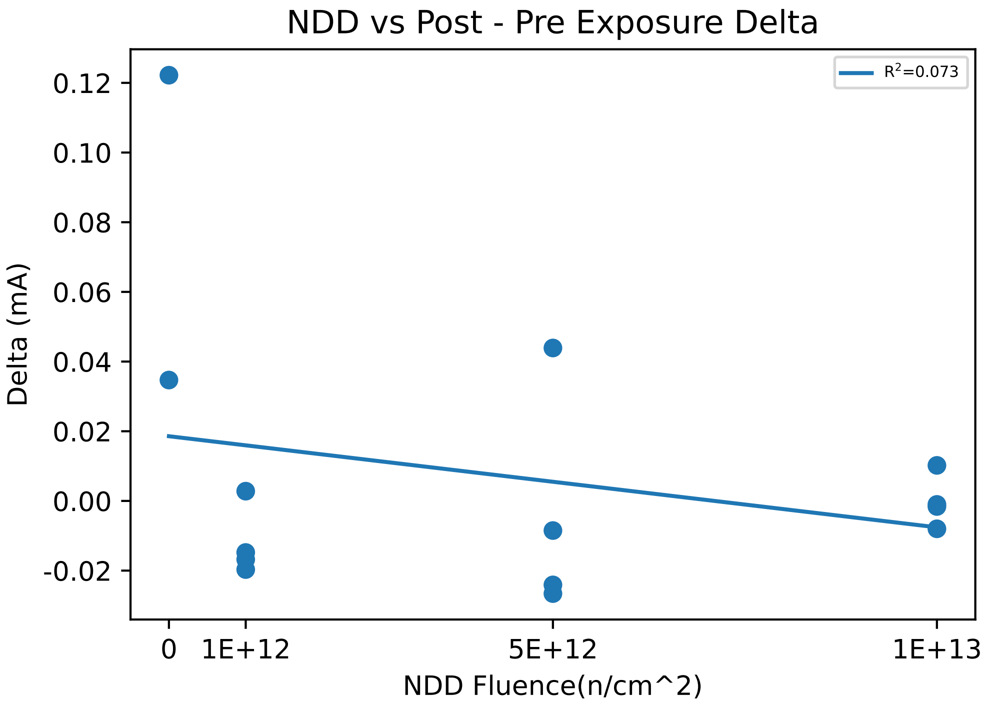
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	6.3922	6.5444	0.1522
2	0	Correlation	6.4625	6.5564	0.0939
30	1e+12	NDD unbiased	6.5163	6.422	-0.0943
31	1e+12	NDD unbiased	6.3972	6.5418	0.1446
32	1e+12	NDD unbiased	6.3606	6.387	0.0264
33	1e+12	NDD unbiased	6.2994	6.3022	0.0028
44	5e+12	NDD unbiased	6.2473	6.2846	0.0373
45	5e+12	NDD unbiased	6.4081	6.4223	0.0142
46	5e+12	NDD unbiased	6.351	6.388	0.037
47	5e+12	NDD unbiased	6.4001	6.4244	0.0243
50	1e+13	NDD unbiased	6.5134	6.4979	-0.0155
51	1e+13	NDD unbiased	6.3489	6.3908	0.0419
52	1e+13	NDD unbiased	6.4074	6.4211	0.0137
53	1e+13	NDD unbiased	6.5213	6.5191	-0.0022

Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	6.3922	6.4274	6.4625	0.04971	6.5444	6.5504	6.5564	0.0084853	0.0939	0.12305	0.1522	0.041224
1e+12	6.2994	6.3934	6.5163	0.091343	6.3022	6.4132	6.5418	0.099369	-0.0943	0.019875	0.1446	0.098194
5e+12	6.2473	6.3516	6.4081	0.07399	6.2846	6.3798	6.4244	0.06564	0.0142	0.0282	0.0373	0.011127
1e+13	6.3489	6.4478	6.5213	0.083903	6.3908	6.4572	6.5191	0.061102	-0.0155	0.009475	0.0419	0.024693

Device Test: 35.7 I_OP_HS_PWM_500KHZ(_Iop HS BOOT PWM 500kHz VIN_10V)





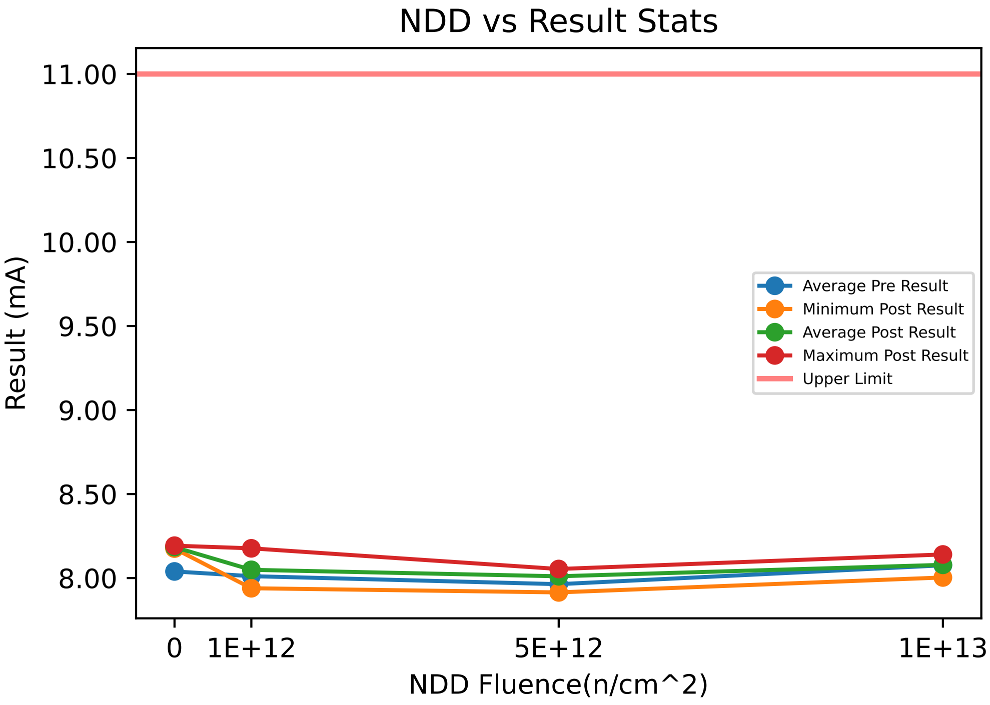
Test Results (Upper Limit = 6.5 (mA))

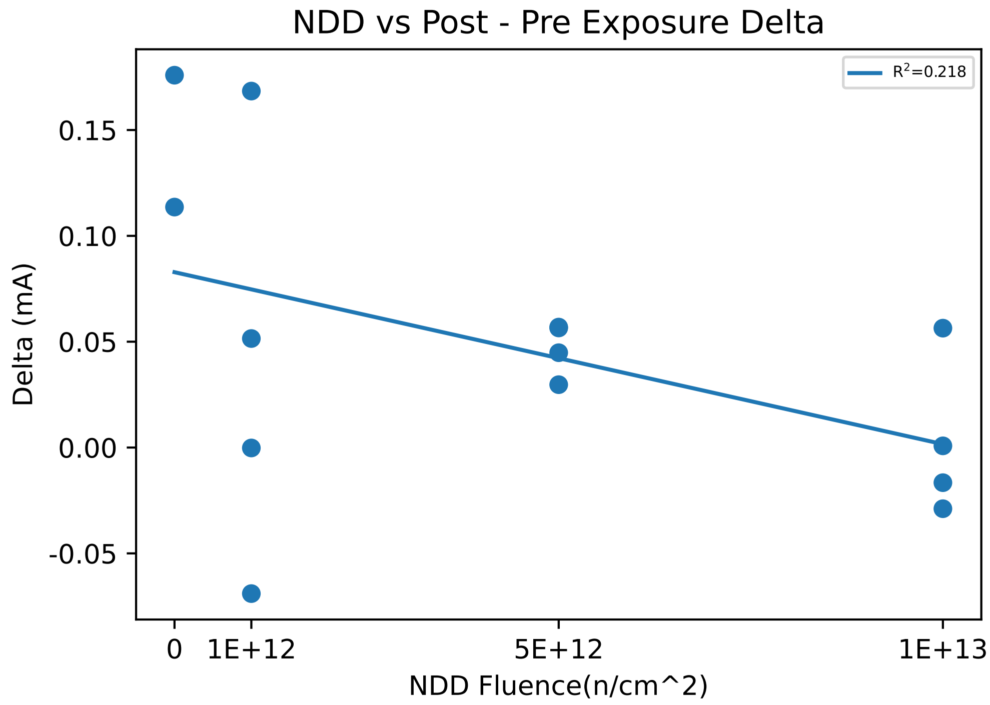
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	4.5866	4.7088	0.1222
2	0	Correlation	4.6686	4.7033	0.0347
30	1e+12	NDD unbiased	4.5986	4.5818	-0.0168
31	1e+12	NDD unbiased	4.5973	4.5776	-0.0197
32	1e+12	NDD unbiased	4.6044	4.5896	-0.0148
33	1e+12	NDD unbiased	4.6949	4.6977	0.0028
44	5e+12	NDD unbiased	4.6808	4.6567	-0.0241
45	5e+12	NDD unbiased	4.5661	4.61	0.0439
46	5e+12	NDD unbiased	4.6206	4.594	-0.0266
47	5e+12	NDD unbiased	4.6205	4.612	-0.0085
50	1e+13	NDD unbiased	4.5414	4.5398	-0.0016
51	1e+13	NDD unbiased	4.6044	4.5964	-0.008
52	1e+13	NDD unbiased	4.5489	4.5591	0.0102
53	1e+13	NDD unbiased	4.6821	4.6811	-0.001

Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.5866	4.6276	4.6686	0.057983	4.7033	4.706	4.7088	0.0038891	0.0347	0.07845	0.1222	0.061872
1e+12	4.5973	4.6238	4.6949	0.0475	4.5776	4.6117	4.6977	0.057565	-0.0197	-0.012125	0.0028	0.010151
5e+12	4.5661	4.622	4.6808	0.046856	4.594	4.6182	4.6567	0.026917	-0.0266	-0.003825	0.0439	0.032809
1e+13	4.5414	4.5942	4.6821	0.064988	4.5398	4.5941	4.6811	0.062577	-0.008	-0.0001	0.0102	0.0075622

Device Test: 35.8 I_OP_LS_PWM_1MHZ(_Iop LS VIN PWM 1MHz VIN_10V)





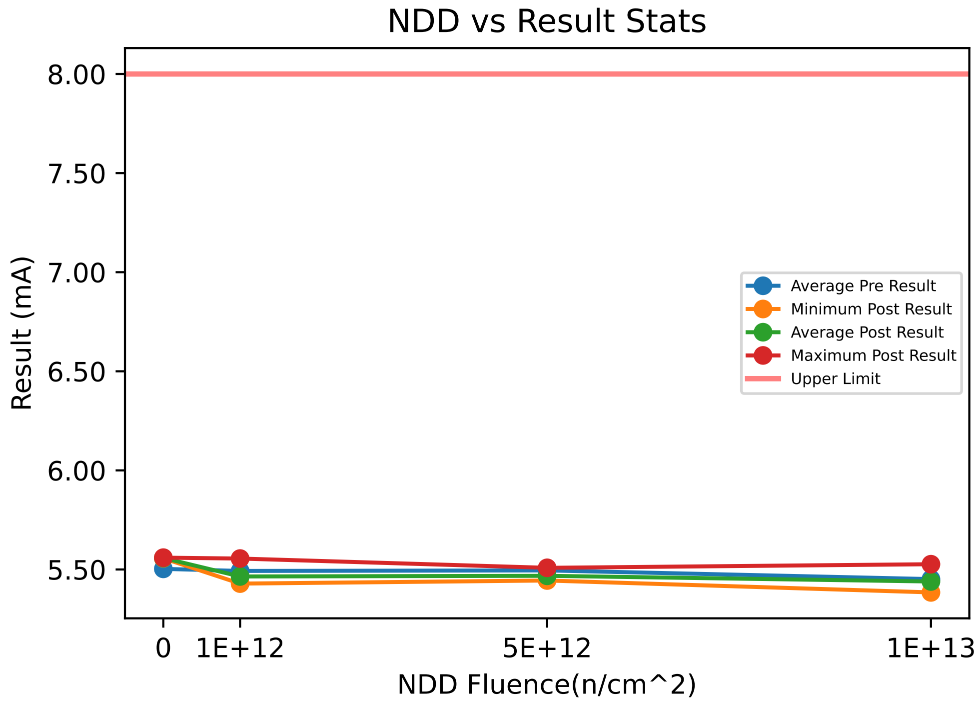
Test Results (Upper Limit = 11.0 (mA))

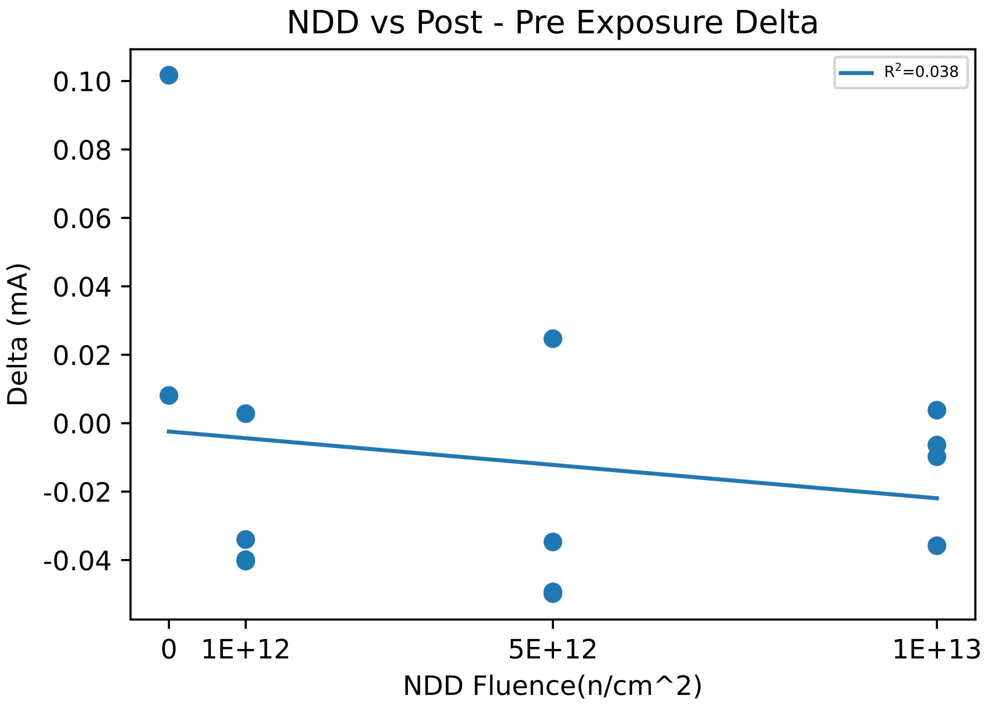
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	7.9996	8.1755	0.1759
2	0	Correlation	8.0791	8.1927	0.1136
30	1e+12	NDD unbiased	8.1262	8.0572	-0.069
31	1e+12	NDD unbiased	8.0085	8.1769	0.1684
32	1e+12	NDD unbiased	7.9708	8.0223	0.0515
33	1e+12	NDD unbiased	7.9395	7.9393	-0.0002
44	5e+12	NDD unbiased	7.8577	7.9146	0.0569
45	5e+12	NDD unbiased	8.0215	8.0512	0.0297
46	5e+12	NDD unbiased	7.9659	8.0224	0.0565
47	5e+12	NDD unbiased	8.0091	8.0539	0.0448
50	1e+13	NDD unbiased	8.1494	8.1205	-0.0289
51	1e+13	NDD unbiased	7.947	8.0034	0.0564
52	1e+13	NDD unbiased	8.0496	8.0504	0.0008
53	1e+13	NDD unbiased	8.157	8.1404	-0.0166

Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	7.9996	8.0394	8.0791	0.056215	8.1755	8.1841	8.1927	0.012162	0.1136	0.14475	0.1759	0.044053
1e+12	7.9395	8.0113	8.1262	0.081661	7.9393	8.0489	8.1769	0.098611	-0.069	0.037675	0.1684	0.10016
5e+12	7.8577	7.9636	8.0215	0.074482	7.9146	8.0105	8.0539	0.06552	0.0297	0.046975	0.0569	0.012811
1e+13	7.947	8.0757	8.157	0.098803	8.0034	8.0787	8.1404	0.063312	-0.0289	0.002925	0.0564	0.037675

Device Test: 35.9 I_OP_HS_PWM_1MHZ(_Iop HS BOOT PWM 1MHz VIN_10V)


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

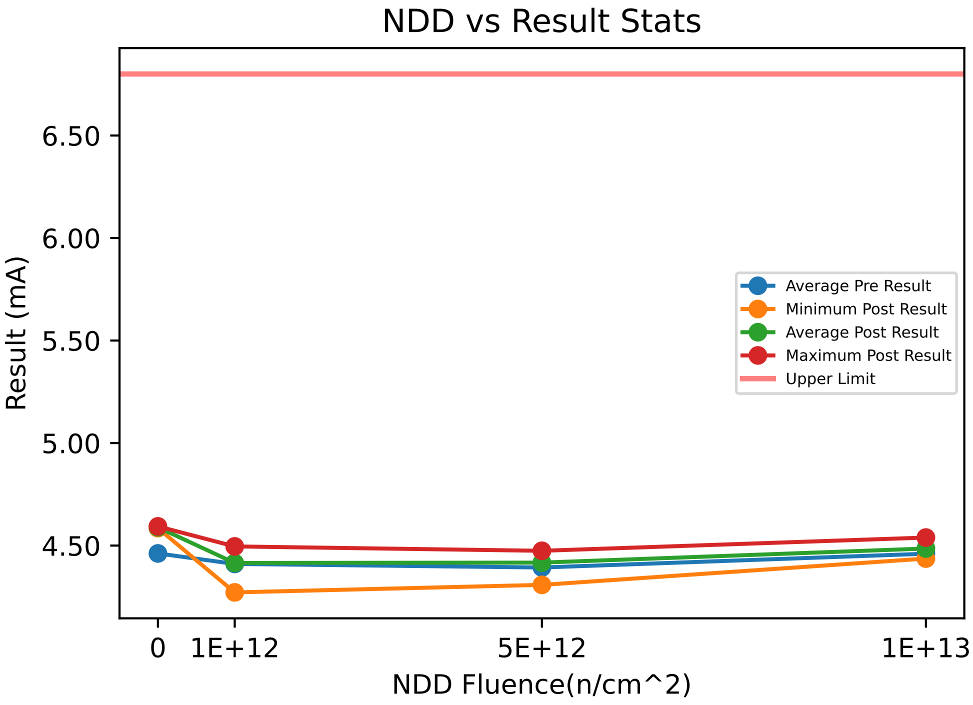
Test Results (Upper Limit = 8.0 (mA))

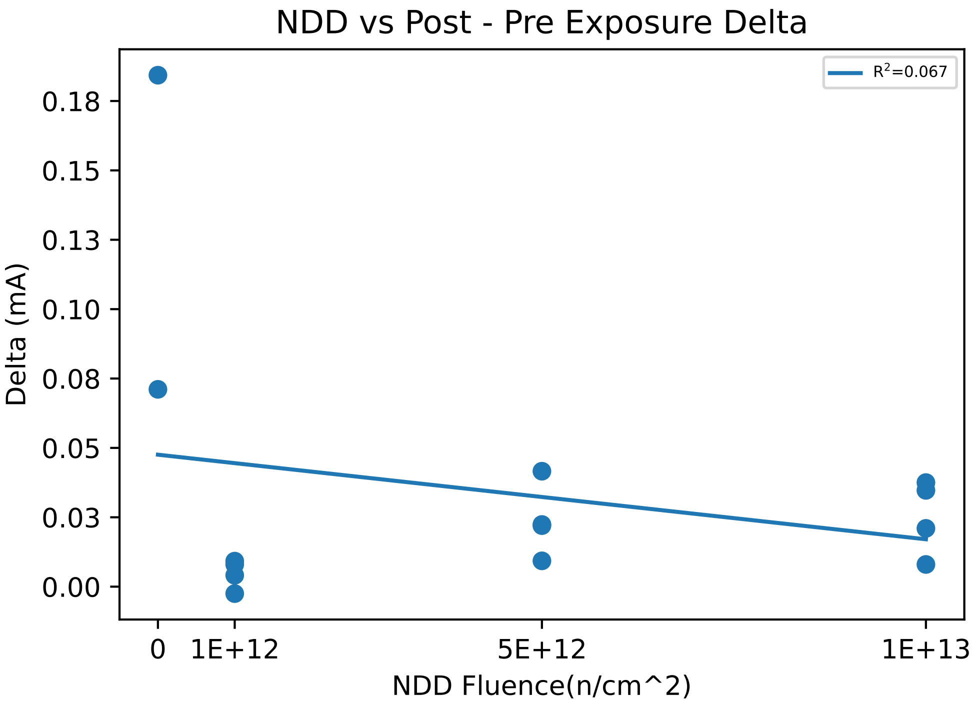
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	5.4579	5.5596	0.1017
2	0	Correlation	5.5482	5.5563	0.0081
30	1e+12	NDD unbiased	5.4708	5.4309	-0.0399
31	1e+12	NDD unbiased	5.469	5.4287	-0.0403
32	1e+12	NDD unbiased	5.4781	5.4441	-0.034
33	1e+12	NDD unbiased	5.5523	5.5551	0.0028
44	5e+12	NDD unbiased	5.5576	5.5083	-0.0493
45	5e+12	NDD unbiased	5.4343	5.459	0.0247
46	5e+12	NDD unbiased	5.4941	5.4443	-0.0498
47	5e+12	NDD unbiased	5.4949	5.4602	-0.0347
50	1e+13	NDD unbiased	5.3941	5.3843	-0.0098
51	1e+13	NDD unbiased	5.4753	5.4395	-0.0358
52	1e+13	NDD unbiased	5.4033	5.4071	0.0038
53	1e+13	NDD unbiased	5.5329	5.5265	-0.0064

Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.4579	5.503	5.5482	0.063852	5.5563	5.5579	5.5596	0.0023335	0.0081	0.0549	0.1017	0.066185
1e+12	5.469	5.4925	5.5523	0.040027	5.4287	5.4647	5.5551	0.060649	-0.0403	-0.02785	0.0028	0.020635
5e+12	5.4343	5.4952	5.5576	0.050345	5.4443	5.468	5.5083	0.027854	-0.0498	-0.027275	0.0247	0.035351
1e+13	5.3941	5.4514	5.5329	0.065346	5.3843	5.4394	5.5265	0.062358	-0.0358	-0.01205	0.0038	0.016855

Device Test: 36.0 IQ_LS_PWM(_Iq LS VIN PWM VIN_12V)





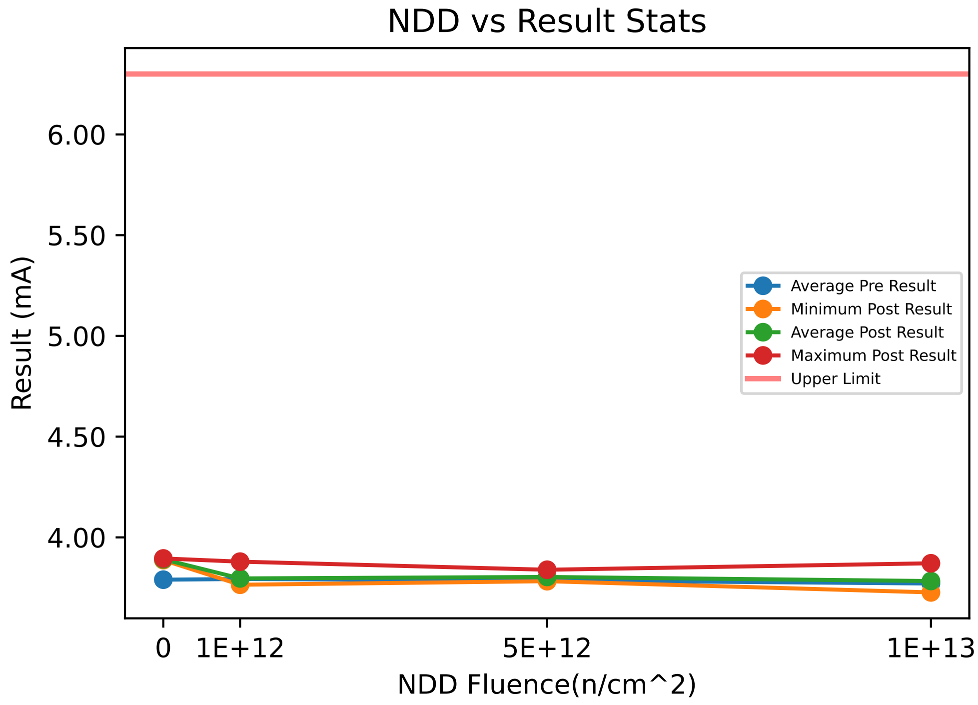
Test Results (Upper Limit = 6.8 (mA))

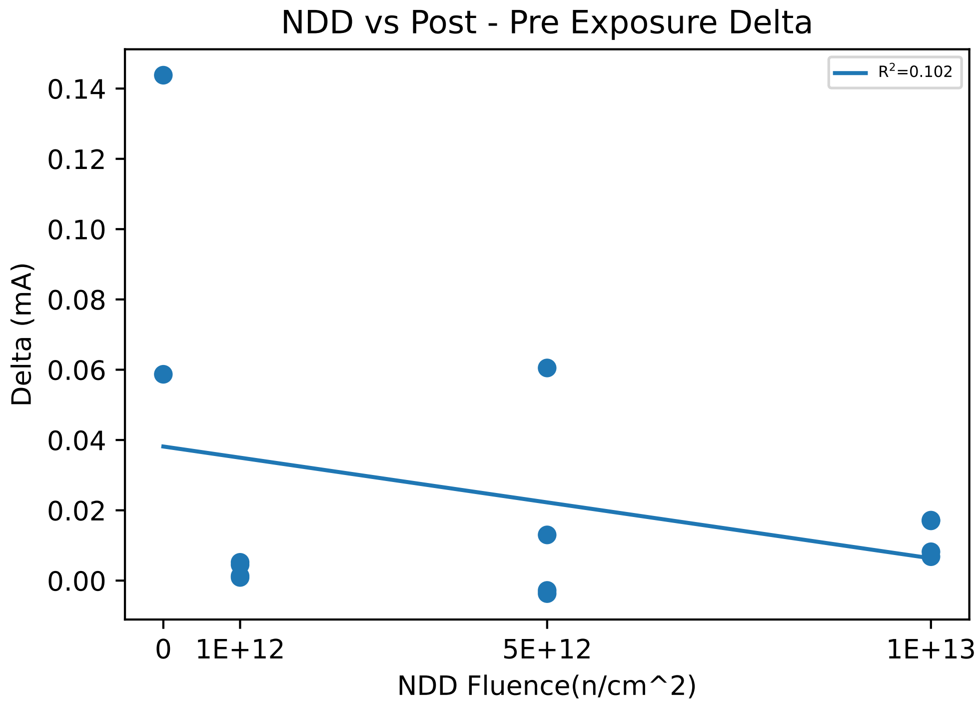
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	4.4093	4.5936	0.1843
2	0	Correlation	4.514	4.5851	0.0711
30	1e+12	NDD unbiased	4.4878	4.4958	0.008
31	1e+12	NDD unbiased	4.4927	4.4902	-0.0025
32	1e+12	NDD unbiased	4.3989	4.403	0.0041
33	1e+12	NDD unbiased	4.2624	4.2716	0.0092
44	5e+12	NDD unbiased	4.2859	4.3083	0.0224
45	5e+12	NDD unbiased	4.4306	4.4722	0.0416
46	5e+12	NDD unbiased	4.3905	4.4125	0.022
47	5e+12	NDD unbiased	4.4652	4.4745	0.0093
50	1e+13	NDD unbiased	4.467	4.475	0.008
51	1e+13	NDD unbiased	4.5044	4.5391	0.0347
52	1e+13	NDD unbiased	4.3991	4.4366	0.0375
53	1e+13	NDD unbiased	4.4705	4.4915	0.021

Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.4093	4.4617	4.514	0.074034	4.5851	4.5893	4.5936	0.0060104	0.0711	0.1277	0.1843	0.080044
1e+12	4.2624	4.4104	4.4927	0.1077	4.2716	4.4151	4.4958	0.10471	-0.0025	0.0047	0.0092	0.0052707
5e+12	4.2859	4.3931	4.4652	0.077682	4.3083	4.4169	4.4745	0.077866	0.0093	0.023825	0.0416	0.01332
1e+13	4.3991	4.4603	4.5044	0.044118	4.4366	4.4855	4.5391	0.042467	0.008	0.0253	0.0375	0.013601

Device Test: 36.1 IQ_HS_PWM(_Iq HS BOOT PWM VIN_12V)


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

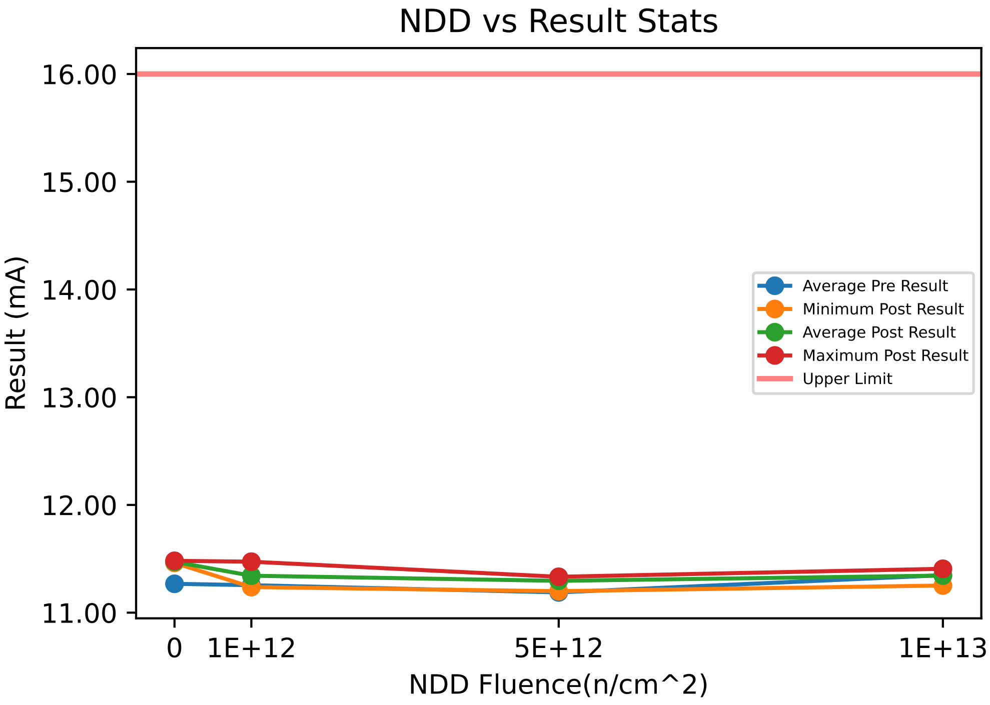
Test Results (Upper Limit = 6.3 (mA))

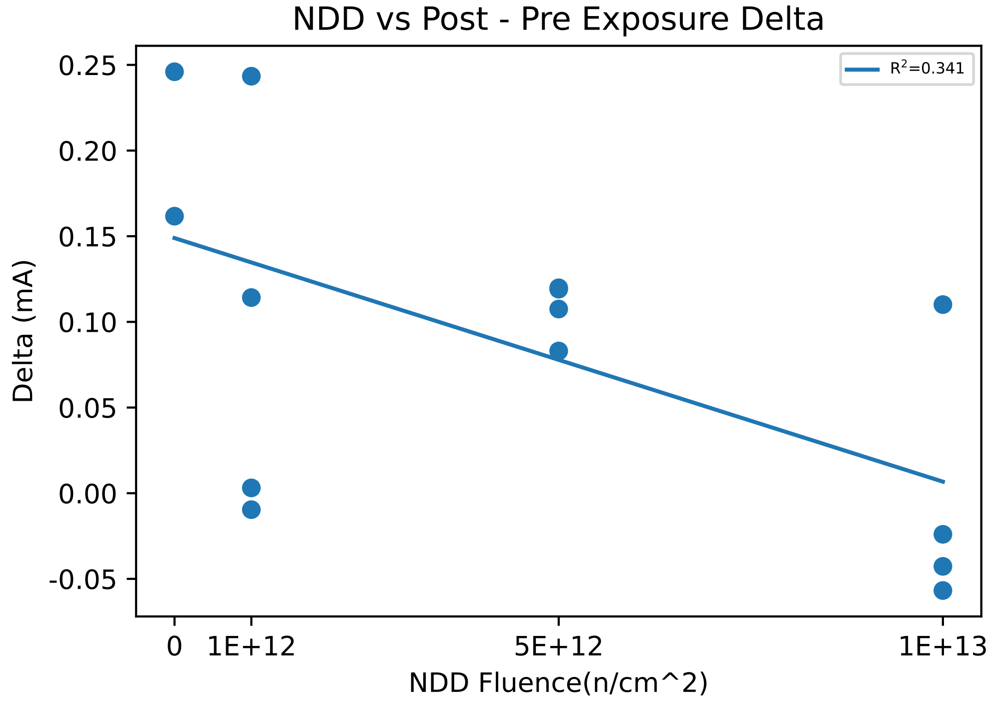
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	3.7516	3.8954	0.1438
2	0	Correlation	3.8284	3.8871	0.0587
30	1e+12	NDD unbiased	3.7667	3.768	0.0013
31	1e+12	NDD unbiased	3.764	3.7649	0.0009
32	1e+12	NDD unbiased	3.7685	3.773	0.0045
33	1e+12	NDD unbiased	3.8743	3.8795	0.0052
44	5e+12	NDD unbiased	3.843	3.8393	-0.0037
45	5e+12	NDD unbiased	3.7344	3.7949	0.0605
46	5e+12	NDD unbiased	3.7853	3.7825	-0.0028
47	5e+12	NDD unbiased	3.7844	3.7974	0.013
50	1e+13	NDD unbiased	3.7201	3.7269	0.0068
51	1e+13	NDD unbiased	3.7722	3.7892	0.017
52	1e+13	NDD unbiased	3.7285	3.7457	0.0172
53	1e+13	NDD unbiased	3.8632	3.8714	0.0082

Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.7516	3.79	3.8284	0.054306	3.8871	3.8913	3.8954	0.005869	0.0587	0.10125	0.1438	0.060175
1e+12	3.764	3.7934	3.8743	0.053982	3.7649	3.7963	3.8795	0.055534	0.0009	0.002975	0.0052	0.0021899
5e+12	3.7344	3.7868	3.843	0.044393	3.7825	3.8035	3.8393	0.024724	-0.0037	0.01675	0.0605	0.030158
1e+13	3.7201	3.771	3.8632	0.065573	3.7269	3.7833	3.8714	0.064268	0.0068	0.0123	0.0172	0.0055726

Device Test: 36.10 I_OP_LS_PWM_2MHZ(_Iop LS VIN PWM 2MHz VIN_12V)


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

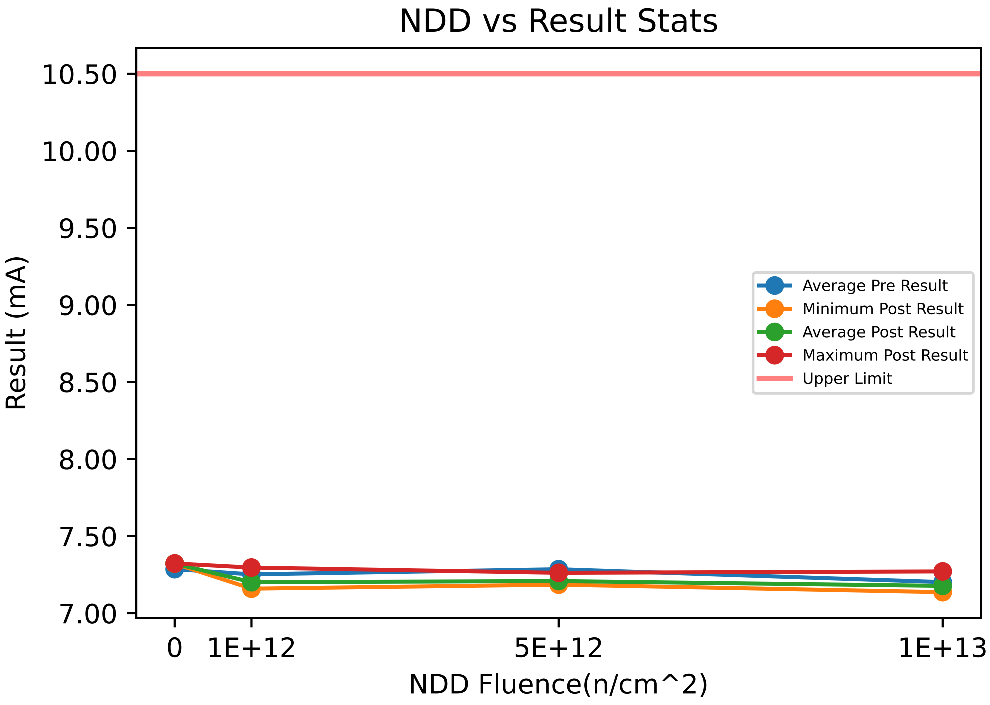
Test Results (Upper Limit = 16.0 (mA))

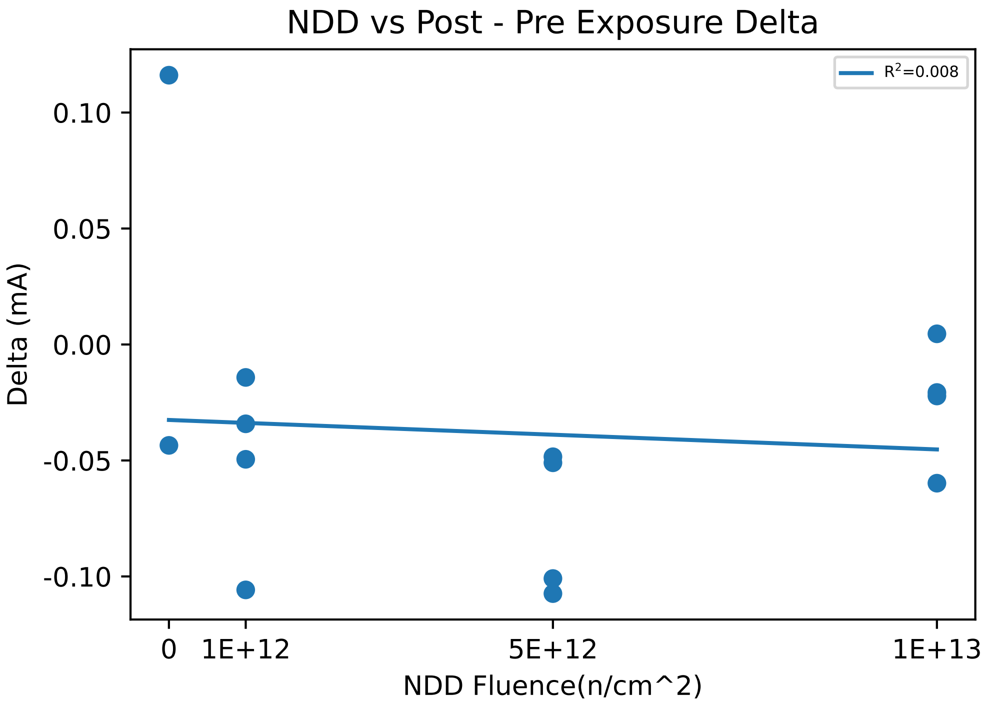
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	11.216	11.462	0.246
2	0	Correlation	11.319	11.481	0.1617
30	1e+12	NDD unbiased	11.347	11.35	0.0031
31	1e+12	NDD unbiased	11.23	11.473	0.2434
32	1e+12	NDD unbiased	11.197	11.311	0.1142
33	1e+12	NDD unbiased	11.247	11.238	-0.0096
44	5e+12	NDD unbiased	11.08	11.2	0.1191
45	5e+12	NDD unbiased	11.248	11.331	0.083
46	5e+12	NDD unbiased	11.198	11.318	0.1199
47	5e+12	NDD unbiased	11.226	11.333	0.1075
50	1e+13	NDD unbiased	11.445	11.388	-0.0568
51	1e+13	NDD unbiased	11.142	11.252	0.1101
52	1e+13	NDD unbiased	11.355	11.331	-0.024
53	1e+13	NDD unbiased	11.45	11.407	-0.0427

Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	11.216	11.268	11.319	0.073115	11.462	11.472	11.481	0.013506	0.1617	0.20385	0.246	0.059609
1e+12	11.197	11.255	11.347	0.06477	11.238	11.343	11.473	0.098526	-0.0096	0.087775	0.2434	0.11771
5e+12	11.08	11.188	11.248	0.074614	11.2	11.296	11.333	0.064328	0.083	0.10738	0.1199	0.01721
1e+13	11.142	11.348	11.45	0.14406	11.252	11.344	11.407	0.069685	-0.0568	-0.00335	0.1101	0.076817

Device Test: 36.11 I_OP_HS_PWM_2MHZ(_Iop HS BOOT PWM 2MHz VIN_12V)


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

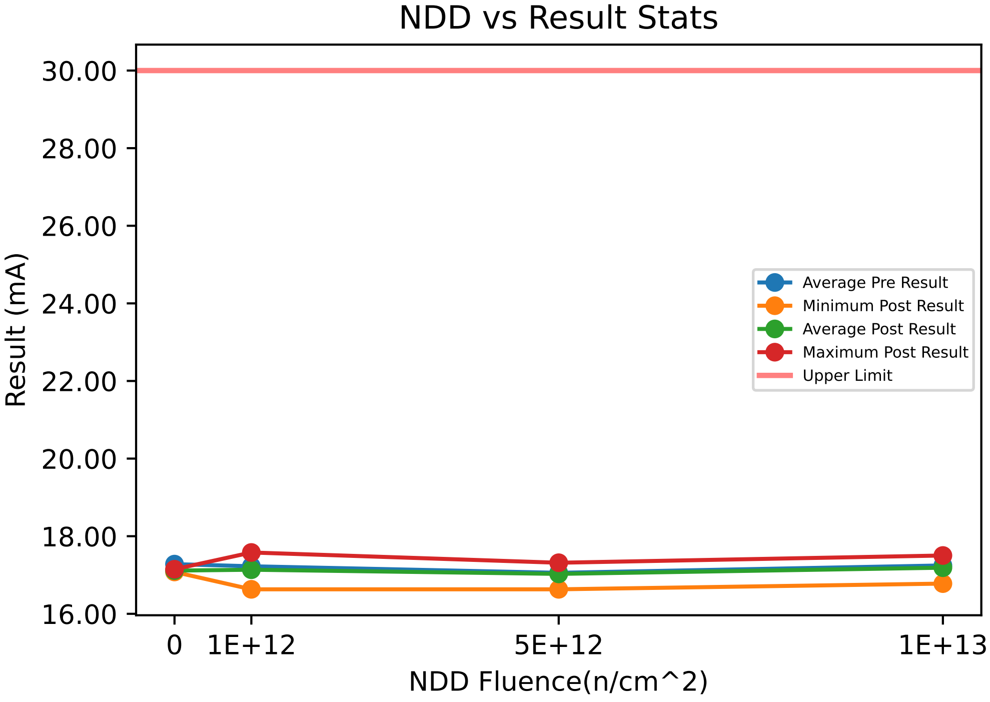
Test Results (Upper Limit = 10.5 (mA))

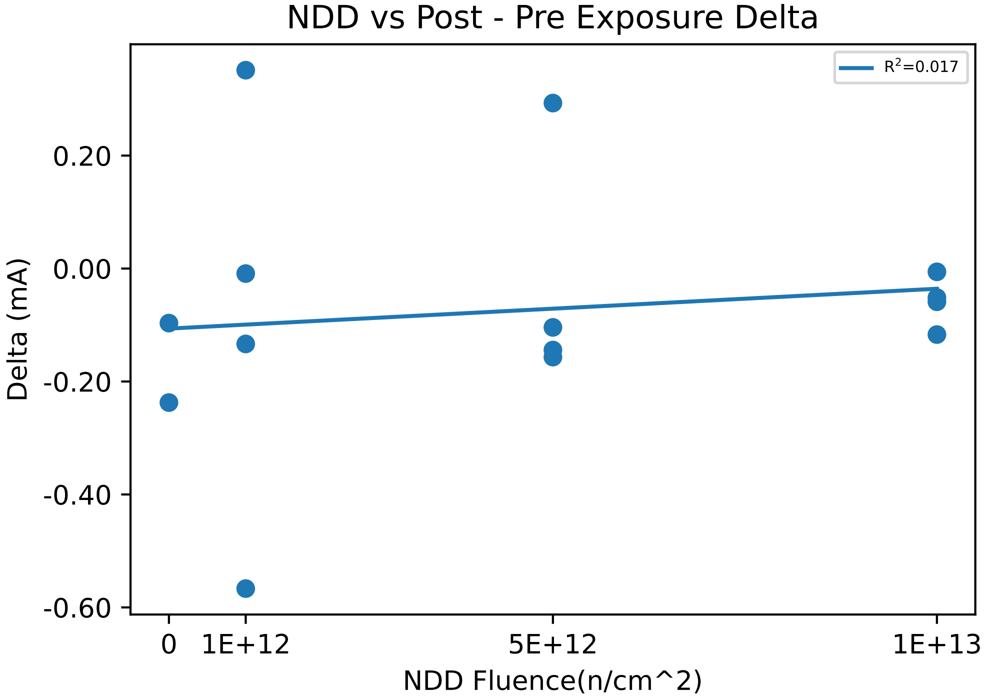
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	7.2057	7.3218	0.1161
2	0	Correlation	7.3663	7.3228	-0.0435
30	1e+12	NDD unbiased	7.2169	7.1827	-0.0342
31	1e+12	NDD unbiased	7.2652	7.1594	-0.1058
32	1e+12	NDD unbiased	7.2161	7.1666	-0.0495
33	1e+12	NDD unbiased	7.3105	7.2963	-0.0142
44	5e+12	NDD unbiased	7.3696	7.2622	-0.1074
45	5e+12	NDD unbiased	7.2338	7.1854	-0.0484
46	5e+12	NDD unbiased	7.2973	7.1964	-0.1009
47	5e+12	NDD unbiased	7.2416	7.1906	-0.051
50	1e+13	NDD unbiased	7.1589	7.1367	-0.0222
51	1e+13	NDD unbiased	7.2173	7.1575	-0.0598
52	1e+13	NDD unbiased	7.14	7.1446	0.0046
53	1e+13	NDD unbiased	7.2919	7.2712	-0.0207

Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	7.2057	7.286	7.3663	0.11356	7.3218	7.3223	7.3228	0.00070711	-0.0435	0.0363	0.1161	0.11285
1e+12	7.2161	7.2522	7.3105	0.045156	7.1594	7.2012	7.2963	0.064111	-0.1058	-0.050925	-0.0142	0.039335
5e+12	7.2338	7.2856	7.3696	0.062749	7.1854	7.2086	7.2622	0.035982	-0.1074	-0.076925	-0.0484	0.031566
1e+13	7.14	7.202	7.2919	0.068356	7.1367	7.1775	7.2712	0.063052	-0.0598	-0.024525	0.0046	0.026537

Device Test: 36.12 I_OP_LS_PWM_5MHZ(_Iop LS VIN PWM 5MHz VIN_12V)





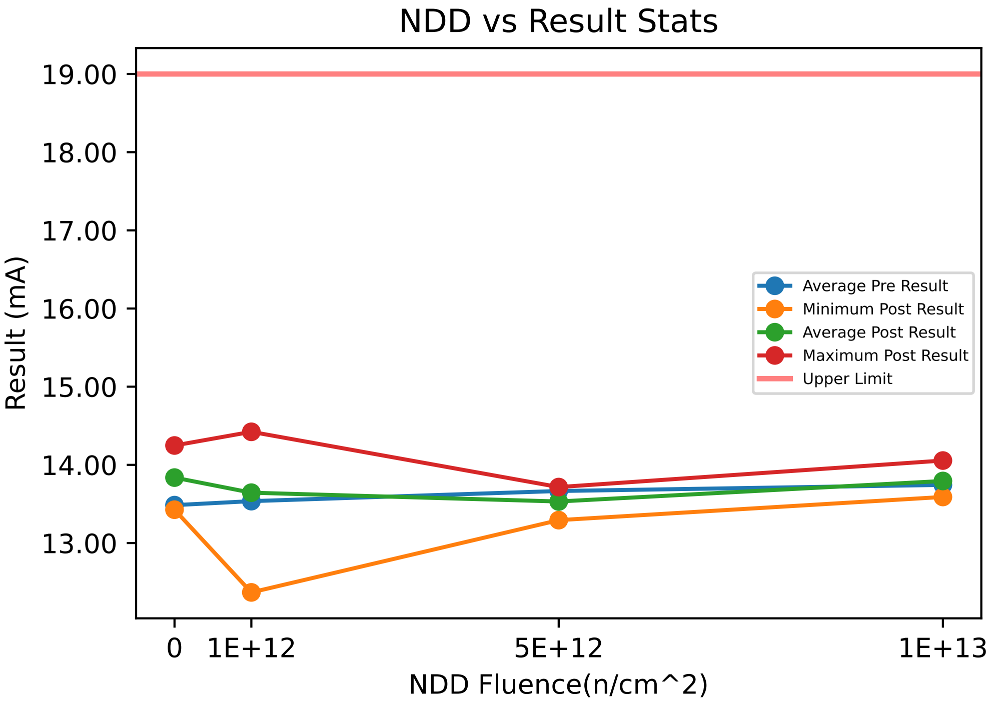
Test Results (Upper Limit = 30.0 (mA))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	17.316	17.079	-0.2373
2	0	Correlation	17.245	17.148	-0.0966
30	1e+12	NDD unbiased	17.704	17.138	-0.5667
31	1e+12	NDD unbiased	17.229	17.58	0.3512
32	1e+12	NDD unbiased	17.328	17.195	-0.1335
33	1e+12	NDD unbiased	16.64	16.631	-0.0089
44	5e+12	NDD unbiased	16.735	16.631	-0.1042
45	5e+12	NDD unbiased	17.022	17.315	0.293
46	5e+12	NDD unbiased	16.997	16.852	-0.1443
47	5e+12	NDD unbiased	17.473	17.316	-0.1568
50	1e+13	NDD unbiased	16.83	16.779	-0.0514
51	1e+13	NDD unbiased	17.619	17.503	-0.1169
52	1e+13	NDD unbiased	17.338	17.332	-0.0058
53	1e+13	NDD unbiased	17.199	17.14	-0.0588

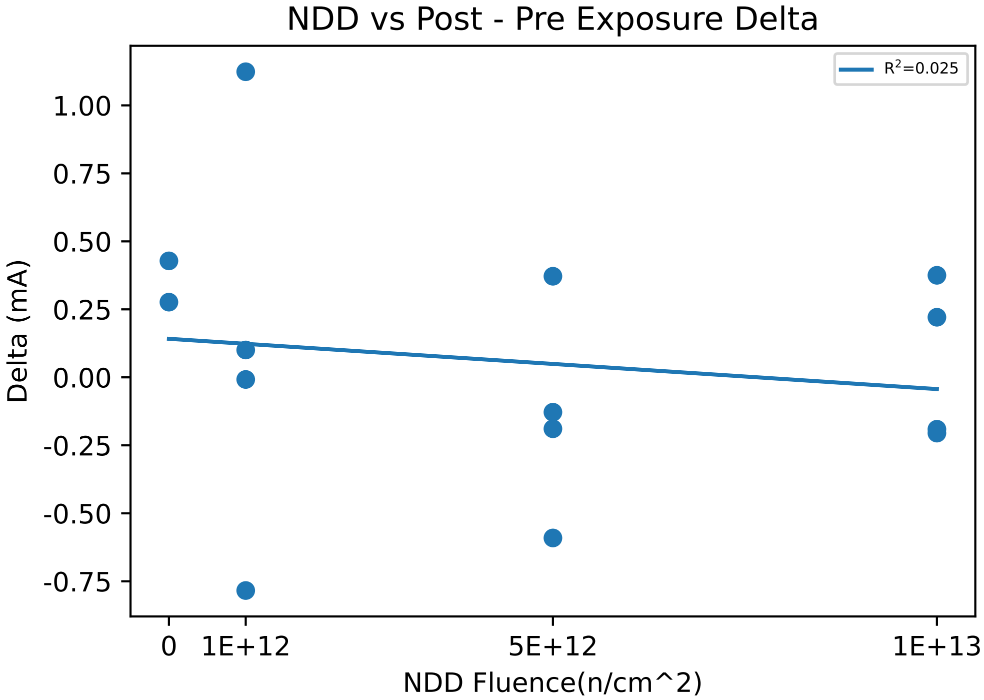
Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	17.245	17.28	17.316	0.050558	17.079	17.114	17.148	0.048932	-0.2373	-0.16695	-0.0966	0.09949
1e+12	16.64	17.226	17.704	0.44072	16.631	17.136	17.58	0.38977	-0.5667	-0.089475	0.3512	0.37876
5e+12	16.735	17.057	17.473	0.30612	16.631	17.029	17.316	0.34325	-0.1568	-0.028075	0.293	0.21522
1e+13	16.83	17.246	17.619	0.32829	16.779	17.188	17.503	0.31077	-0.1169	-0.058225	-0.0058	0.0456

Device Test: 36.13 I_OP_HS_PWM_5MHZ(_Iop HS BOOT PWM 5MHz VIN_12V)



NDD vs Result Stats



NDD vs Post - Pre Exposure Delta

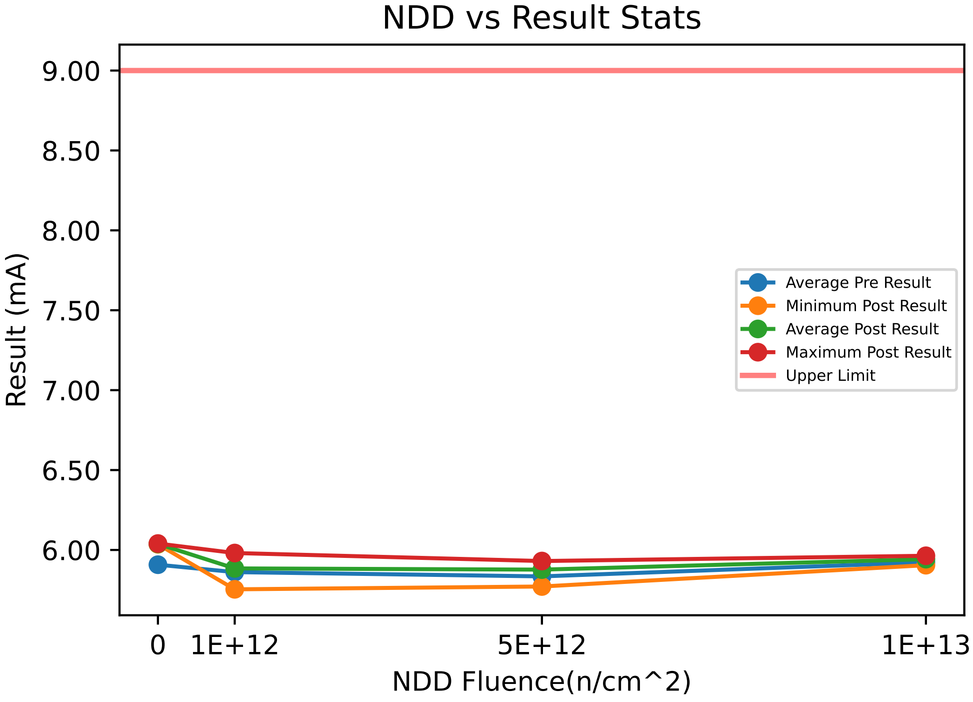
Test Results (Upper Limit = 19.0 (mA))

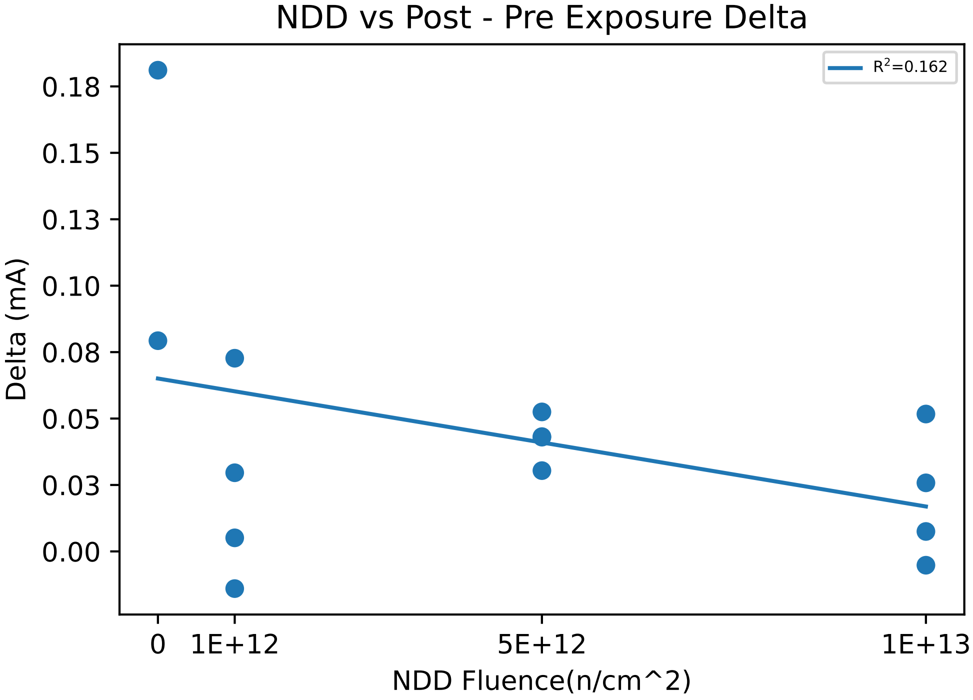
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	13.15	13.427	0.2765
2	0	Correlation	13.82	14.248	0.4282
30	1e+12	NDD unbiased	13.116	14.24	1.1236
31	1e+12	NDD unbiased	14.329	13.545	-0.7838
32	1e+12	NDD unbiased	12.268	12.369	0.1006
33	1e+12	NDD unbiased	14.431	14.423	-0.0078
44	5e+12	NDD unbiased	13.871	13.682	-0.1891
45	5e+12	NDD unbiased	14.026	13.435	-0.5906
46	5e+12	NDD unbiased	13.844	13.716	-0.1282
47	5e+12	NDD unbiased	12.921	13.293	0.3717
50	1e+13	NDD unbiased	14.26	14.055	-0.205
51	1e+13	NDD unbiased	13.255	13.631	0.3752
52	1e+13	NDD unbiased	13.679	13.9	0.221
53	1e+13	NDD unbiased	13.78	13.589	-0.1908

Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	13.15	13.485	13.82	0.47355	13.427	13.837	14.248	0.58082	0.2765	0.35235	0.4282	0.10727
1e+12	12.268	13.536	14.431	1.035	12.369	13.644	14.423	0.93053	-0.7838	0.10815	1.1236	0.7832
5e+12	12.921	13.666	14.026	0.50266	13.293	13.532	13.716	0.2025	-0.5906	-0.13405	0.3717	0.39467
1e+13	13.255	13.744	14.26	0.41266	13.589	13.794	14.055	0.22213	-0.205	0.0501	0.3752	0.29326

Device Test: 36.14 I_OP_LS_IIM_500KHZ(_Iop LS VIN IIM Interlock 500kHz VIN_12V)


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

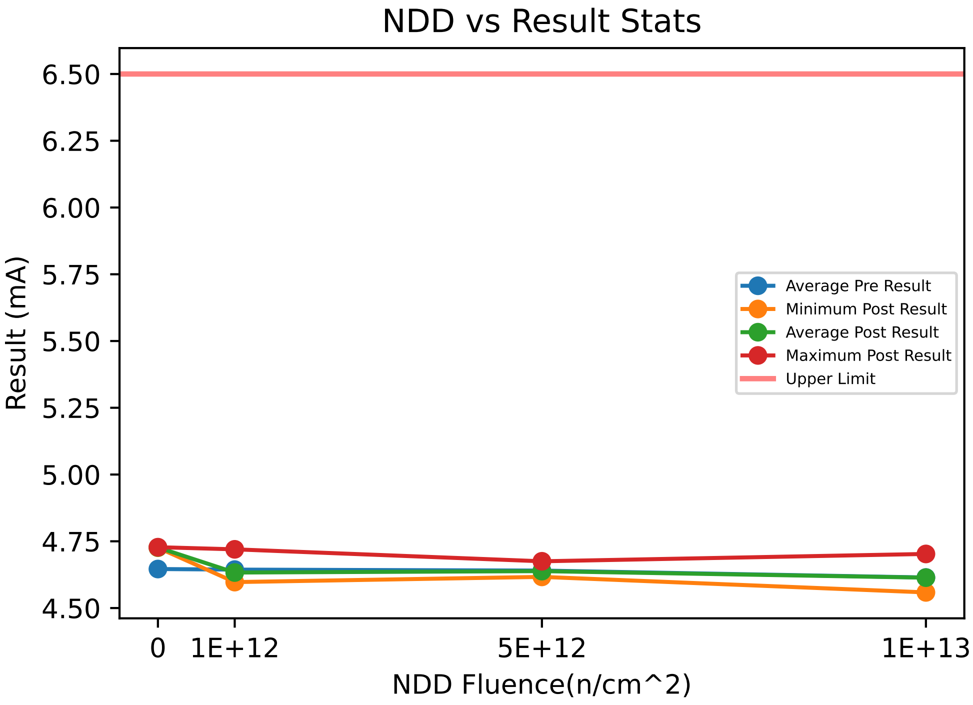
Test Results (Upper Limit = 9.0 (mA))

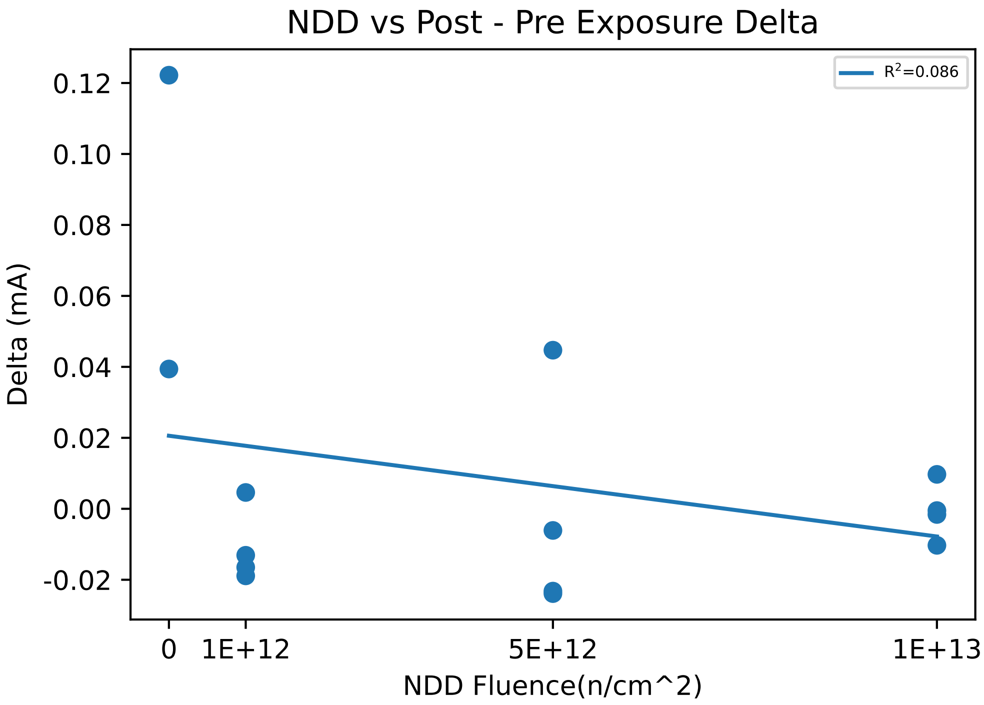
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	5.8591	6.0402	0.1811
2	0	Correlation	5.9564	6.0357	0.0793
30	1e+12	NDD unbiased	5.9514	5.9374	-0.014
31	1e+12	NDD unbiased	5.9081	5.9808	0.0727
32	1e+12	NDD unbiased	5.837	5.8666	0.0296
33	1e+12	NDD unbiased	5.7486	5.7537	0.0051
44	5e+12	NDD unbiased	5.7281	5.7713	0.0432
45	5e+12	NDD unbiased	5.8749	5.9274	0.0525
46	5e+12	NDD unbiased	5.8354	5.8784	0.043
47	5e+12	NDD unbiased	5.9003	5.9307	0.0304
50	1e+13	NDD unbiased	5.9538	5.9486	-0.0052
51	1e+13	NDD unbiased	5.9008	5.9525	0.0517
52	1e+13	NDD unbiased	5.8789	5.9047	0.0258
53	1e+13	NDD unbiased	5.9561	5.9636	0.0075

Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.8591	5.9078	5.9564	0.068801	6.0357	6.038	6.0402	0.003182	0.0793	0.1302	0.1811	0.071983
1e+12	5.7486	5.8613	5.9514	0.088694	5.7537	5.8846	5.9808	0.099165	-0.014	0.02335	0.0727	0.037428
5e+12	5.7281	5.8347	5.9003	0.075902	5.7713	5.8769	5.9307	0.074383	0.0304	0.042275	0.0525	0.0090728
1e+13	5.8789	5.9224	5.9561	0.038646	5.9047	5.9423	5.9636	0.025892	-0.0052	0.01995	0.0517	0.024697

Device Test: 36.15 I_OP_HS_IIM_500KHZ(_Iop HS BOOT IIM Interlock 500kHz VIN_12V)





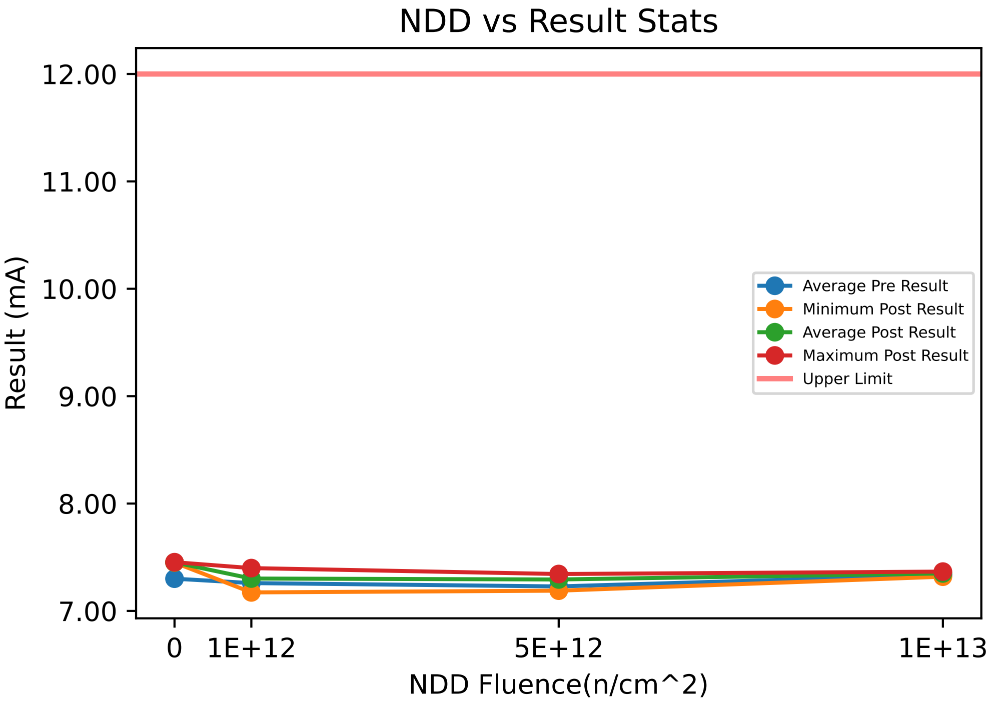
Test Results (Upper Limit = 6.5 (mA))

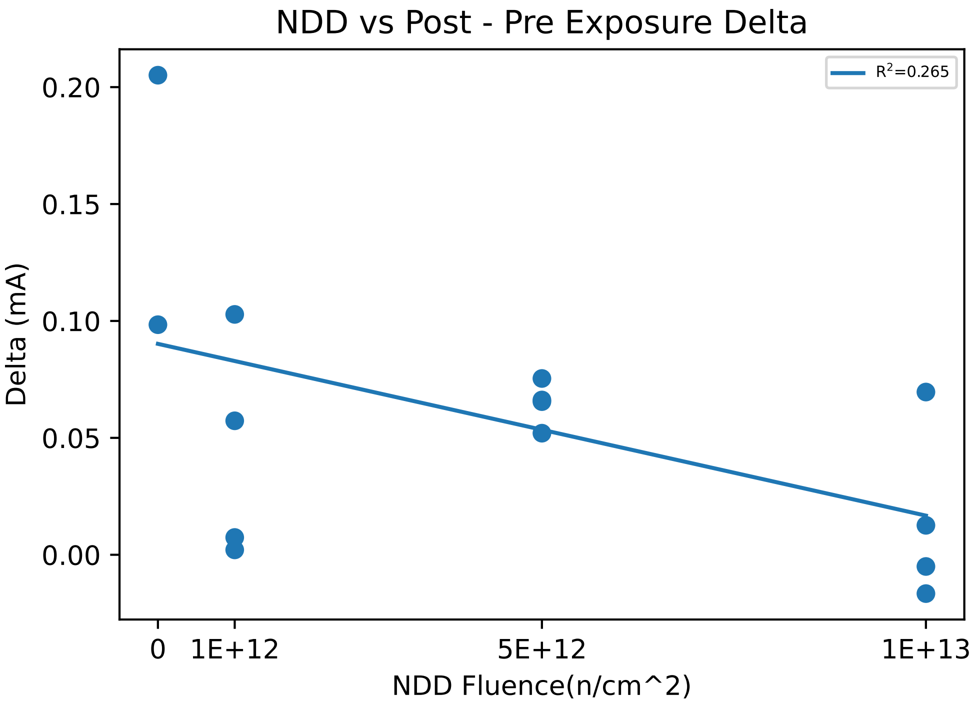
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	4.6057	4.7279	0.1222
2	0	Correlation	4.6866	4.726	0.0394
30	1e+12	NDD unbiased	4.6186	4.6021	-0.0165
31	1e+12	NDD unbiased	4.6161	4.5972	-0.0189
32	1e+12	NDD unbiased	4.6258	4.6127	-0.0131
33	1e+12	NDD unbiased	4.7153	4.7199	0.0046
44	5e+12	NDD unbiased	4.699	4.6751	-0.0239
45	5e+12	NDD unbiased	4.5834	4.6281	0.0447
46	5e+12	NDD unbiased	4.6399	4.6167	-0.0232
47	5e+12	NDD unbiased	4.6391	4.633	-0.0061
50	1e+13	NDD unbiased	4.5602	4.5586	-0.0016
51	1e+13	NDD unbiased	4.6246	4.6143	-0.0103
52	1e+13	NDD unbiased	4.5698	4.5795	0.0097
53	1e+13	NDD unbiased	4.7031	4.7026	-0.0005

Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.6057	4.6462	4.6866	0.057205	4.726	4.727	4.7279	0.0013435	0.0394	0.0808	0.1222	0.058548
1e+12	4.6161	4.644	4.7153	0.047744	4.5972	4.633	4.7199	0.05831	-0.0189	-0.010975	0.0046	0.010653
5e+12	4.5834	4.6403	4.699	0.047205	4.6167	4.6382	4.6751	0.025514	-0.0239	-0.002125	0.0447	0.032284
1e+13	4.5602	4.6144	4.7031	0.065571	4.5586	4.6138	4.7026	0.063533	-0.0103	-0.000675	0.0097	0.0081888

Device Test: 36.16 I_OP_LS_IIM_1MHZ(_Iop LS VIN IIM Interlock 1MHz VIN_12V)


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

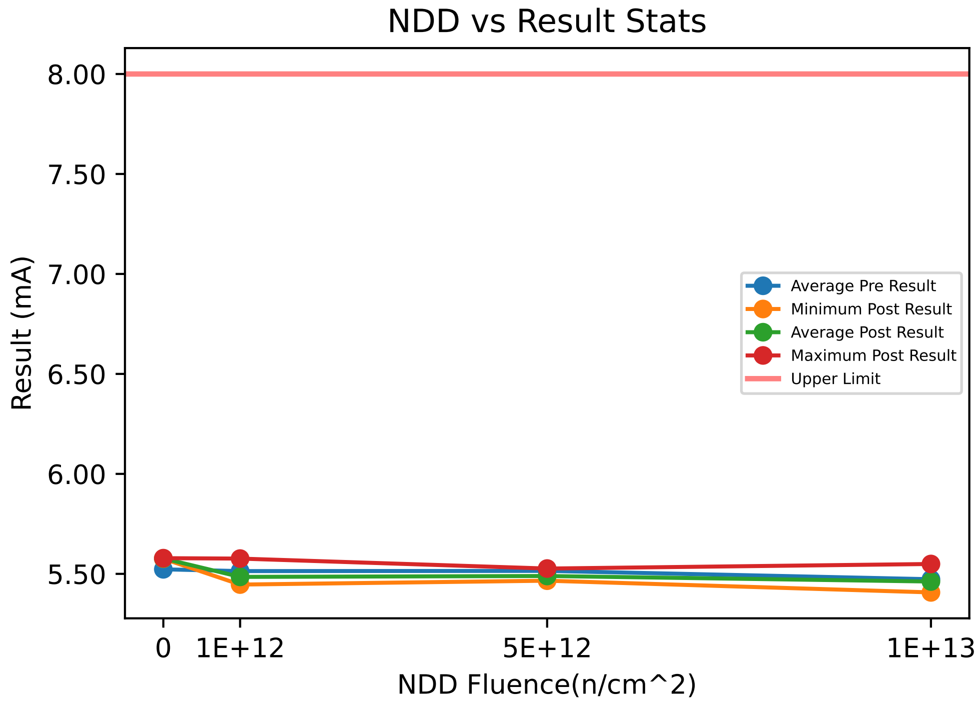
Test Results (Upper Limit = 12.0 (mA))

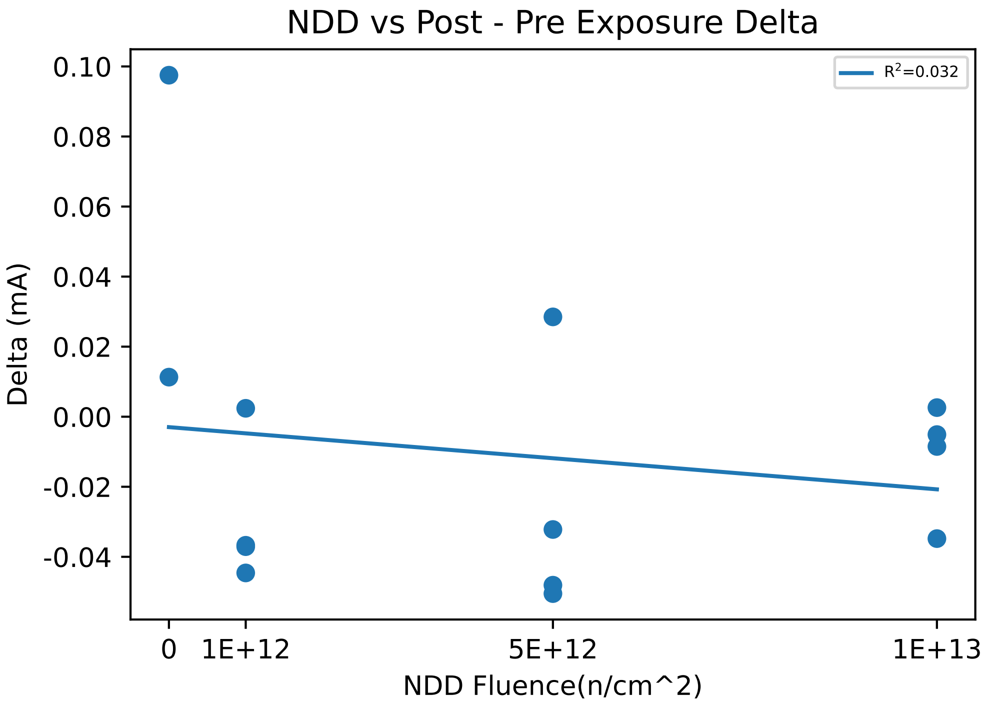
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	7.2488	7.4539	0.2051
2	0	Correlation	7.3519	7.4503	0.0984
30	1e+12	NDD unbiased	7.3441	7.3515	0.0074
31	1e+12	NDD unbiased	7.2962	7.399	0.1028
32	1e+12	NDD unbiased	7.2266	7.2839	0.0573
33	1e+12	NDD unbiased	7.1706	7.1727	0.0021
44	5e+12	NDD unbiased	7.1225	7.1887	0.0662
45	5e+12	NDD unbiased	7.2665	7.3419	0.0754
46	5e+12	NDD unbiased	7.2322	7.2977	0.0655
47	5e+12	NDD unbiased	7.2918	7.3438	0.052
50	1e+13	NDD unbiased	7.3732	7.3566	-0.0166
51	1e+13	NDD unbiased	7.2857	7.3553	0.0696
52	1e+13	NDD unbiased	7.3063	7.3189	0.0126
53	1e+13	NDD unbiased	7.3713	7.3663	-0.005

Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	7.2488	7.3003	7.3519	0.072903	7.4503	7.4521	7.4539	0.0025456	0.0984	0.15175	0.2051	0.075448
1e+12	7.1706	7.2594	7.3441	0.076354	7.1727	7.3018	7.399	0.098158	0.0021	0.0424	0.1028	0.047326
5e+12	7.1225	7.2283	7.2918	0.074611	7.1887	7.293	7.3438	0.072738	0.052	0.064775	0.0754	0.0096376
1e+13	7.2857	7.3341	7.3732	0.044826	7.3189	7.3493	7.3663	0.020836	-0.0166	0.01515	0.0696	0.038233

Device Test: 36.17 I_OP_HS_IIM_1MHZ(_Iop HS BOOT IIM Interlock 1MHz VIN_12V)





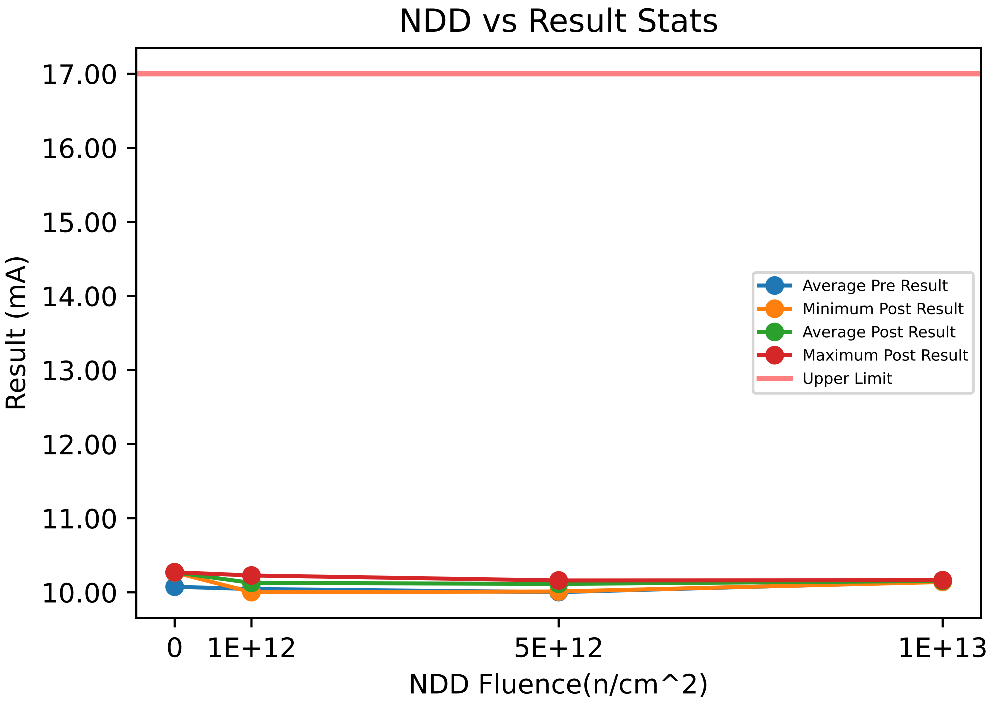
Test Results (Upper Limit = 8.0 (mA))

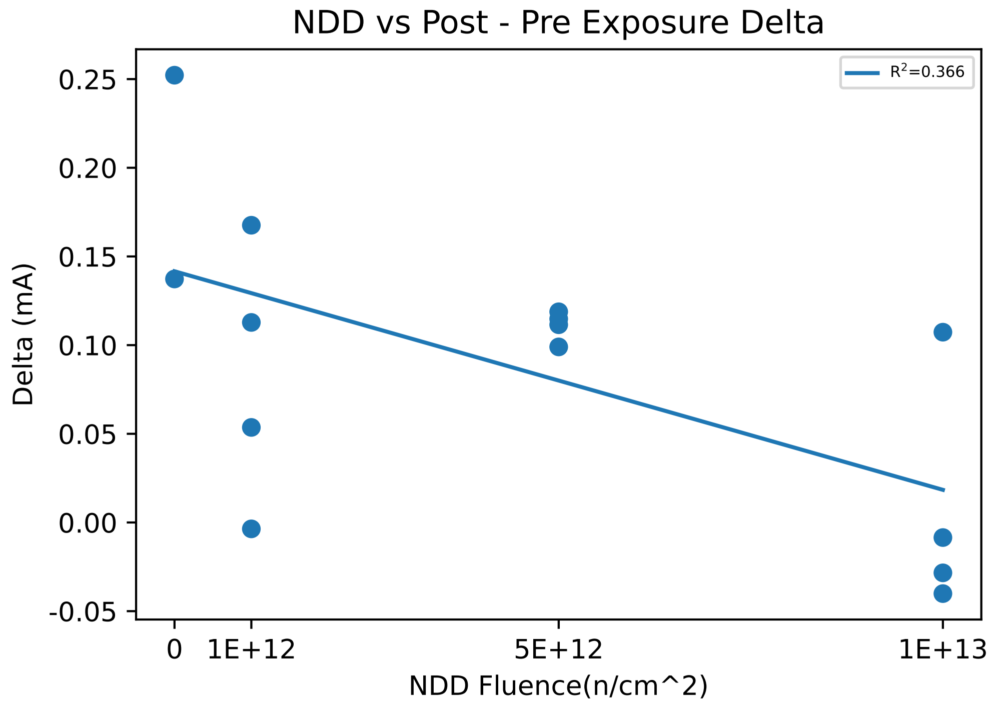
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	5.4783	5.5758	0.0975
2	0	Correlation	5.5672	5.5785	0.0113
30	1e+12	NDD unbiased	5.4886	5.4515	-0.0371
31	1e+12	NDD unbiased	5.4911	5.4465	-0.0446
32	1e+12	NDD unbiased	5.5016	5.4649	-0.0367
33	1e+12	NDD unbiased	5.574	5.5764	0.0024
44	5e+12	NDD unbiased	5.5747	5.5266	-0.0481
45	5e+12	NDD unbiased	5.4516	5.4801	0.0285
46	5e+12	NDD unbiased	5.5163	5.4658	-0.0505
47	5e+12	NDD unbiased	5.5168	5.4846	-0.0322
50	1e+13	NDD unbiased	5.4158	5.4073	-0.0085
51	1e+13	NDD unbiased	5.4969	5.4621	-0.0348
52	1e+13	NDD unbiased	5.4255	5.4281	0.0026
53	1e+13	NDD unbiased	5.5545	5.5494	-0.0051

Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.4783	5.5228	5.5672	0.062862	5.5758	5.5771	5.5785	0.0019092	0.0113	0.0544	0.0975	0.060953
1e+12	5.4886	5.5138	5.574	0.04051	5.4465	5.4848	5.5764	0.061542	-0.0446	-0.029	0.0024	0.021246
5e+12	5.4516	5.5149	5.5747	0.050294	5.4658	5.4893	5.5266	0.026142	-0.0505	-0.025575	0.0285	0.036953
1e+13	5.4158	5.4732	5.5545	0.06517	5.4073	5.4617	5.5494	0.062663	-0.0348	-0.01145	0.0026	0.016244

Device Test: 36.18 I_OP_LS_IIM_2MHZ(_Iop LS VIN IIM Interlock 2MHz VIN_12V)





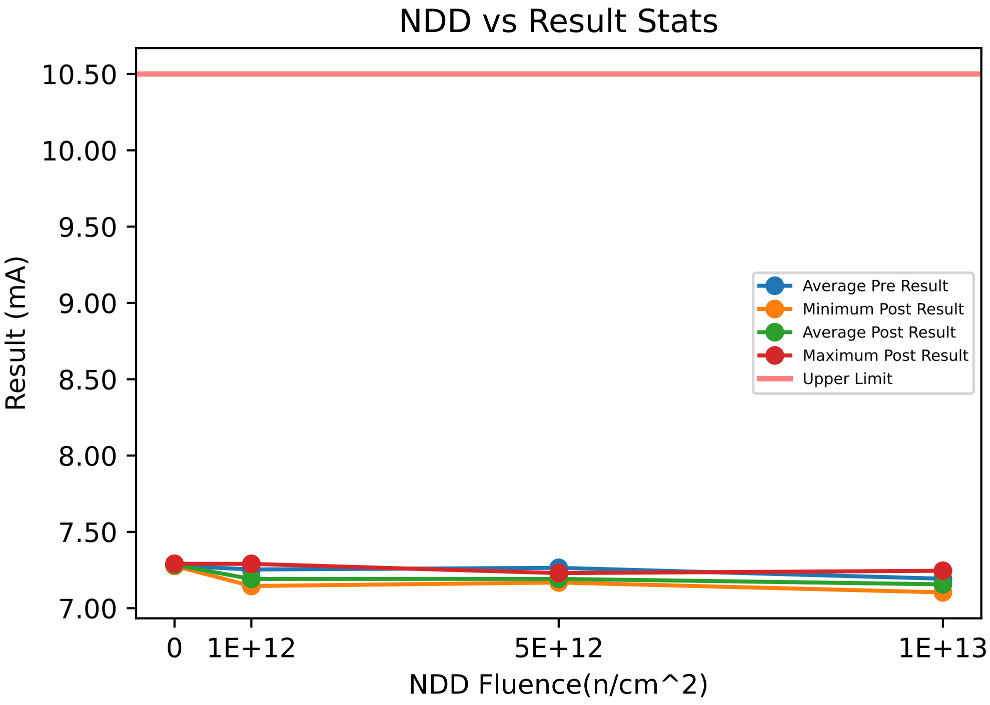
Test Results (Upper Limit = 17.0 (mA))

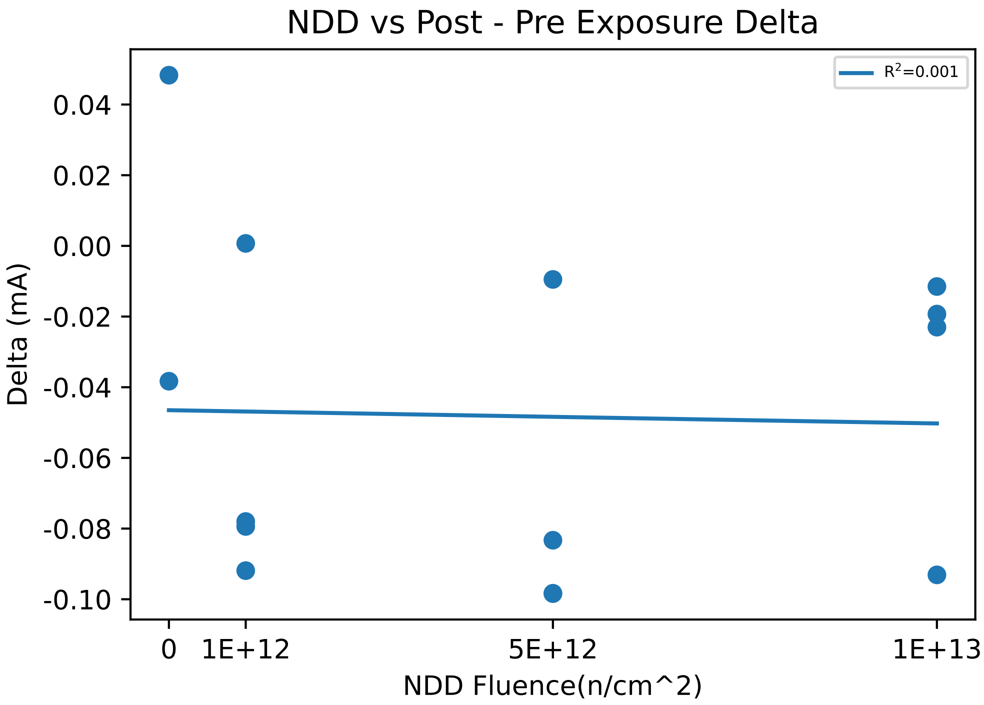
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	10.019	10.271	0.2522
2	0	Correlation	10.132	10.269	0.1373
30	1e+12	NDD unbiased	10.118	10.171	0.0536
31	1e+12	NDD unbiased	10.06	10.228	0.1676
32	1e+12	NDD unbiased	9.9958	10.109	0.1128
33	1e+12	NDD unbiased	10.006	10.003	-0.0036
44	5e+12	NDD unbiased	9.8966	10.011	0.1148
45	5e+12	NDD unbiased	10.039	10.158	0.1188
46	5e+12	NDD unbiased	10.014	10.126	0.1115
47	5e+12	NDD unbiased	10.061	10.16	0.099
50	1e+13	NDD unbiased	10.201	10.161	-0.0401
51	1e+13	NDD unbiased	10.044	10.151	0.1073
52	1e+13	NDD unbiased	10.148	10.139	-0.0085
53	1e+13	NDD unbiased	10.192	10.164	-0.0284

Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	10.019	10.075	10.132	0.079974	10.269	10.27	10.271	0.0012728	0.1373	0.19475	0.2522	0.081247
1e+12	9.9958	10.045	10.118	0.05605	10.003	10.128	10.228	0.096449	-0.0036	0.0826	0.1676	0.073956
5e+12	9.8966	10.003	10.061	0.073378	10.011	10.114	10.16	0.070083	0.099	0.11102	0.1188	0.0085543
1e+13	10.044	10.146	10.201	0.072351	10.139	10.154	10.164	0.011115	-0.0401	0.007575	0.1073	0.067751

Device Test: 36.19 I_OP_HS_IIM_2MHZ(_Iop HS BOOT IIM Interlock 2MHz VIN_12V)





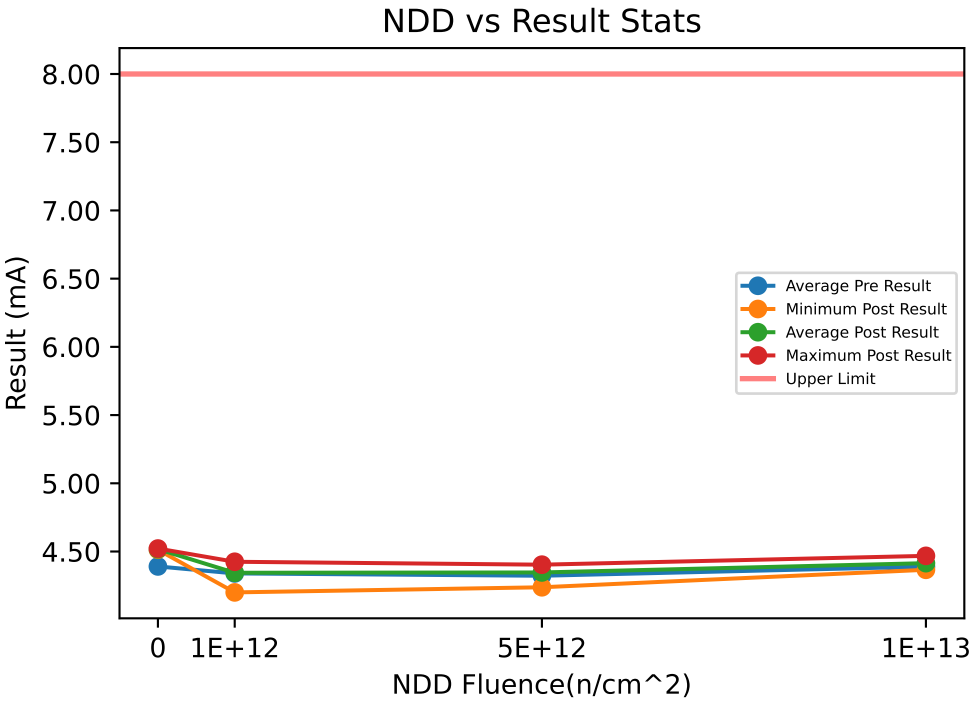
Test Results (Upper Limit = 10.5 (mA))

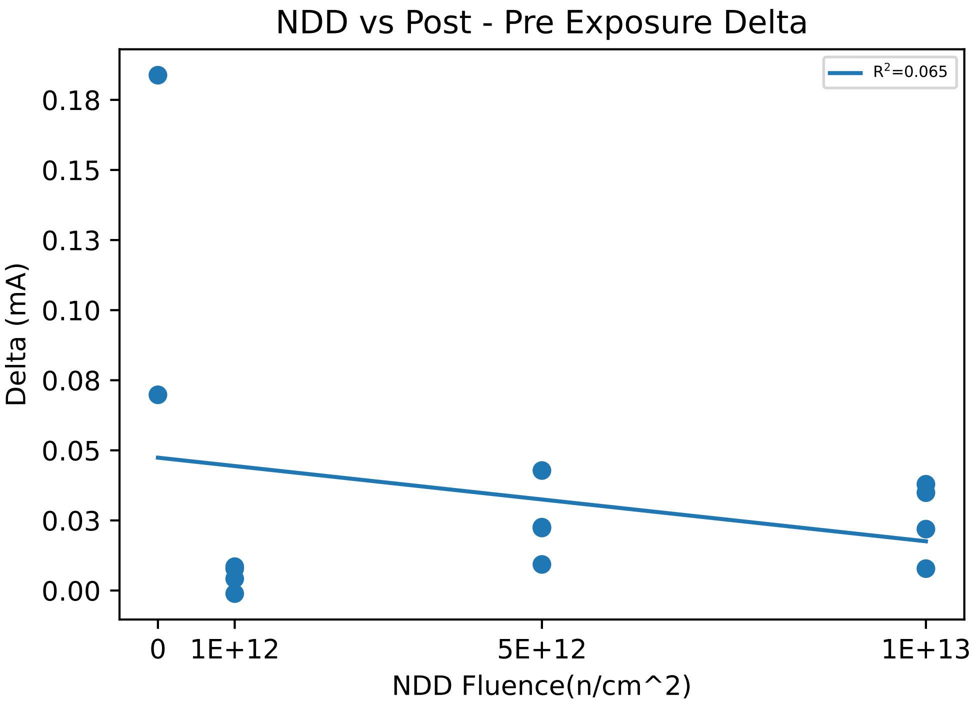
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	7.2284	7.2767	0.0483
2	0	Correlation	7.3295	7.2912	-0.0383
30	1e+12	NDD unbiased	7.2336	7.1542	-0.0794
31	1e+12	NDD unbiased	7.2372	7.1453	-0.0919
32	1e+12	NDD unbiased	7.2545	7.1765	-0.078
33	1e+12	NDD unbiased	7.2896	7.2903	0.0007
44	5e+12	NDD unbiased	7.3282	7.2299	-0.0983
45	5e+12	NDD unbiased	7.1926	7.1831	-0.0095
46	5e+12	NDD unbiased	7.2667	7.1683	-0.0984
47	5e+12	NDD unbiased	7.27	7.1867	-0.0833
50	1e+13	NDD unbiased	7.1265	7.1035	-0.023
51	1e+13	NDD unbiased	7.2428	7.1497	-0.0931
52	1e+13	NDD unbiased	7.1383	7.1268	-0.0115
53	1e+13	NDD unbiased	7.2647	7.2454	-0.0193

Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	7.2284	7.279	7.3295	0.071488	7.2767	7.2839	7.2912	0.010253	-0.0383	0.005	0.0483	0.061235
1e+12	7.2336	7.2537	7.2896	0.025598	7.1453	7.1916	7.2903	0.067112	-0.0919	-0.06215	0.0007	0.042363
5e+12	7.1926	7.2644	7.3282	0.055565	7.1683	7.192	7.2299	0.026492	-0.0984	-0.072375	-0.0095	0.042513
1e+13	7.1265	7.1931	7.2647	0.070794	7.1035	7.1563	7.2454	0.062291	-0.0931	-0.036725	-0.0115	0.037888

Device Test: 36.2 IQ_LS_IIM(_Iq LS VIN IIM Interlock VIN_12V)


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

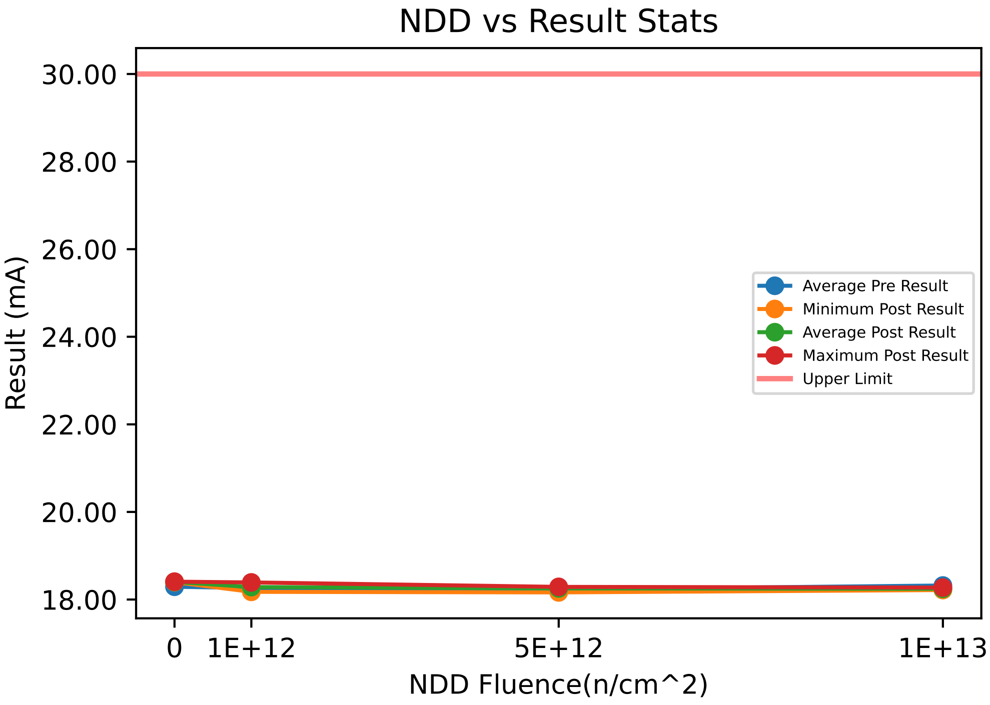
Test Results (Upper Limit = 8.0 (mA))

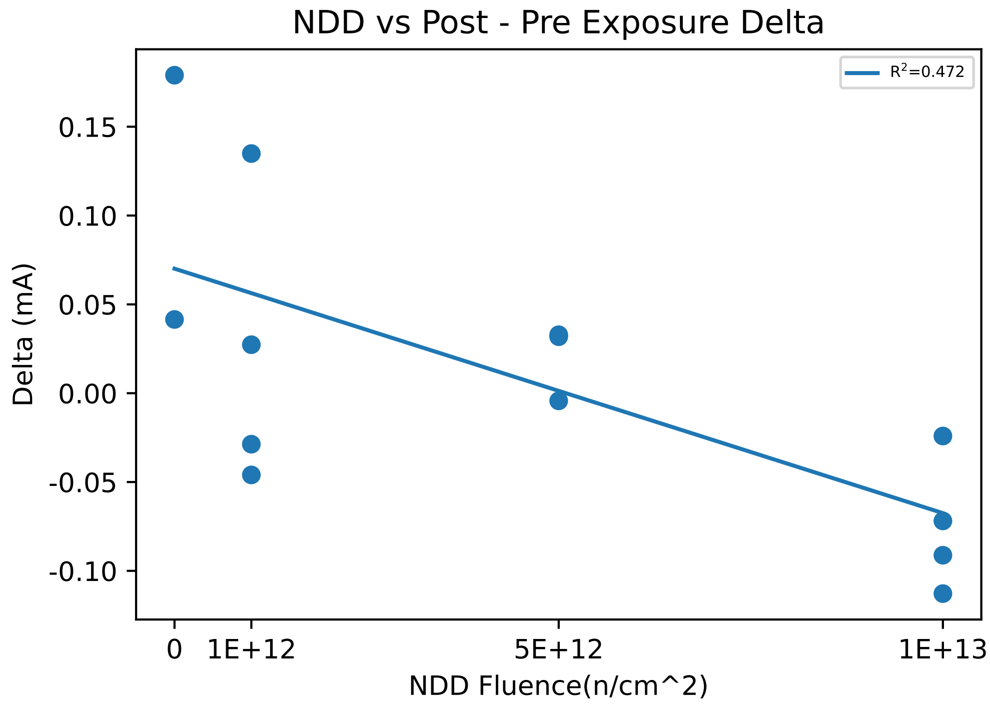
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	4.338	4.5218	0.1838
2	0	Correlation	4.4432	4.513	0.0698
30	1e+12	NDD unbiased	4.417	4.4248	0.0078
31	1e+12	NDD unbiased	4.4209	4.4198	-0.0011
32	1e+12	NDD unbiased	4.3278	4.332	0.0042
33	1e+12	NDD unbiased	4.1918	4.2003	0.0085
44	5e+12	NDD unbiased	4.2153	4.2379	0.0226
45	5e+12	NDD unbiased	4.359	4.4018	0.0428
46	5e+12	NDD unbiased	4.3206	4.3429	0.0223
47	5e+12	NDD unbiased	4.3942	4.4035	0.0093
50	1e+13	NDD unbiased	4.3959	4.4037	0.0078
51	1e+13	NDD unbiased	4.4332	4.4681	0.0349
52	1e+13	NDD unbiased	4.3281	4.366	0.0379
53	1e+13	NDD unbiased	4.3987	4.4206	0.0219

Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.338	4.3906	4.4432	0.074388	4.513	4.5174	4.5218	0.0062225	0.0698	0.1268	0.1838	0.08061
1e+12	4.1918	4.3394	4.4209	0.10737	4.2003	4.3442	4.4248	0.10499	-0.0011	0.00485	0.0085	0.0043913
5e+12	4.2153	4.3223	4.3942	0.077392	4.2379	4.3465	4.4035	0.077705	0.0093	0.02425	0.0428	0.013834
1e+13	4.3281	4.389	4.4332	0.043985	4.366	4.4146	4.4681	0.042344	0.0078	0.025625	0.0379	0.013764

Device Test: 36.20 I_OP_LS_IIM_5MHZ(_Iop LS VIN IIM Interlock 5MHz VIN_12V)


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

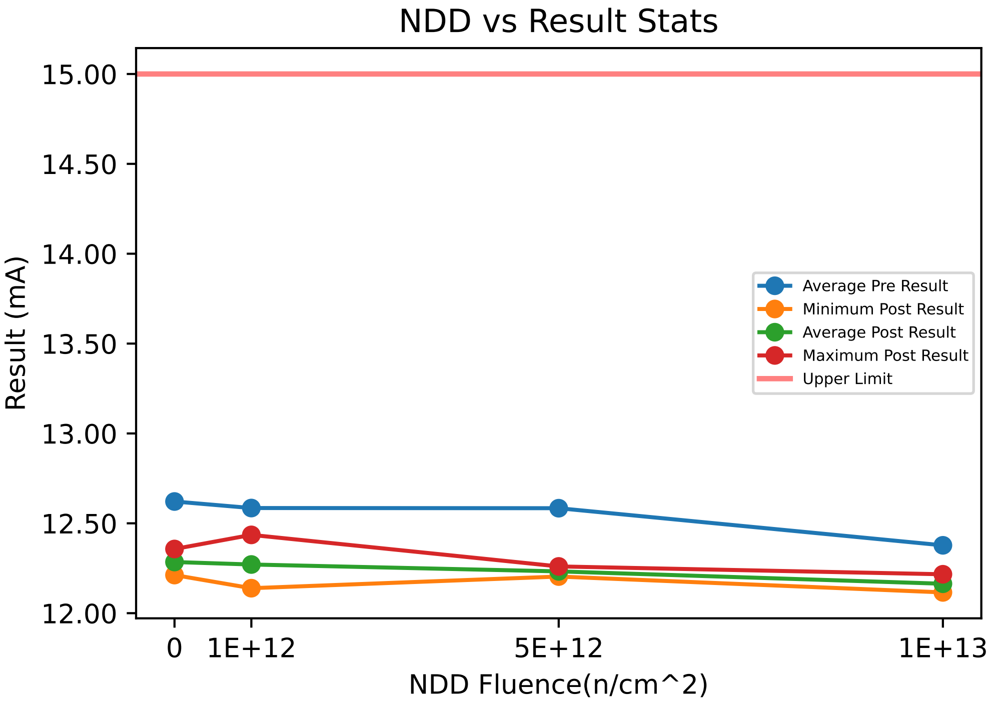
Test Results (Upper Limit = 30.0 (mA))

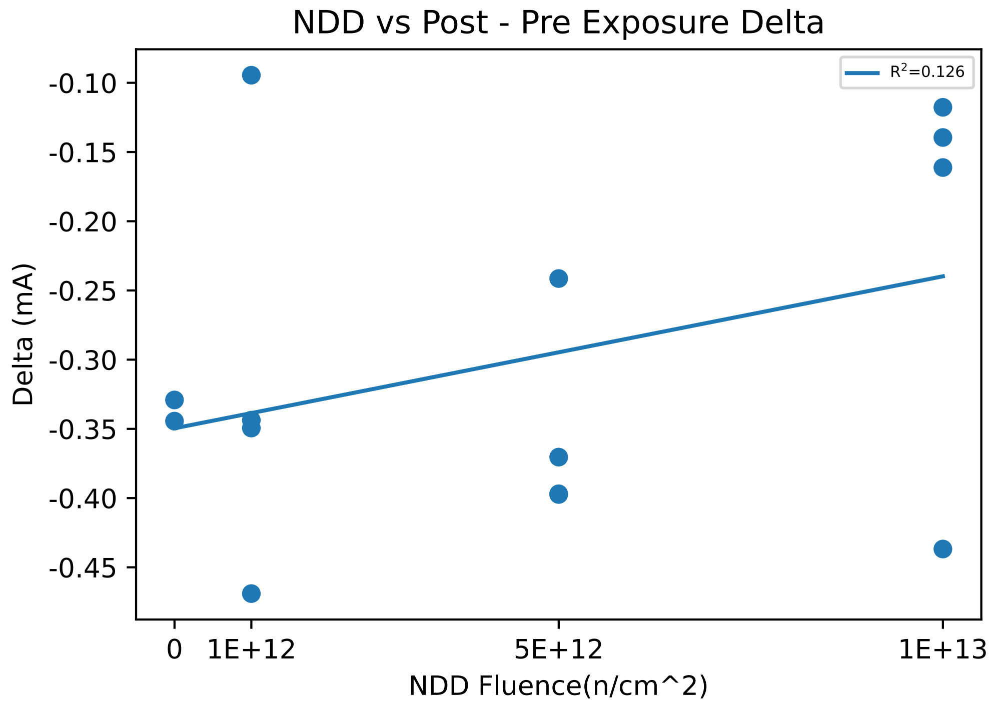
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	18.218	18.397	0.179
2	0	Correlation	18.366	18.408	0.0415
30	1e+12	NDD unbiased	18.355	18.309	-0.046
31	1e+12	NDD unbiased	18.255	18.39	0.1349
32	1e+12	NDD unbiased	18.234	18.261	0.0273
33	1e+12	NDD unbiased	18.204	18.176	-0.0287
44	5e+12	NDD unbiased	18.13	18.163	0.0329
45	5e+12	NDD unbiased	18.249	18.28	0.0318
46	5e+12	NDD unbiased	18.256	18.289	0.0324
47	5e+12	NDD unbiased	18.288	18.284	-0.0043
50	1e+13	NDD unbiased	18.367	18.254	-0.1128
51	1e+13	NDD unbiased	18.241	18.217	-0.0241
52	1e+13	NDD unbiased	18.345	18.273	-0.0719
53	1e+13	NDD unbiased	18.327	18.236	-0.0912

Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	18.218	18.292	18.366	0.10501	18.397	18.402	18.408	0.0077782	0.0415	0.11025	0.179	0.097227
1e+12	18.204	18.262	18.355	0.065556	18.176	18.284	18.39	0.089812	-0.046	0.021875	0.1349	0.081586
5e+12	18.13	18.231	18.288	0.069476	18.163	18.254	18.289	0.060926	-0.0043	0.0232	0.0329	0.018339
1e+13	18.241	18.32	18.367	0.055208	18.217	18.245	18.273	0.024091	-0.1128	-0.075	-0.0241	0.037823

Device Test: 36.21 I_OP_HS_IIM_5MHZ(_Iop HS BOOT IIM Interlock 5MHz VIN_12V)





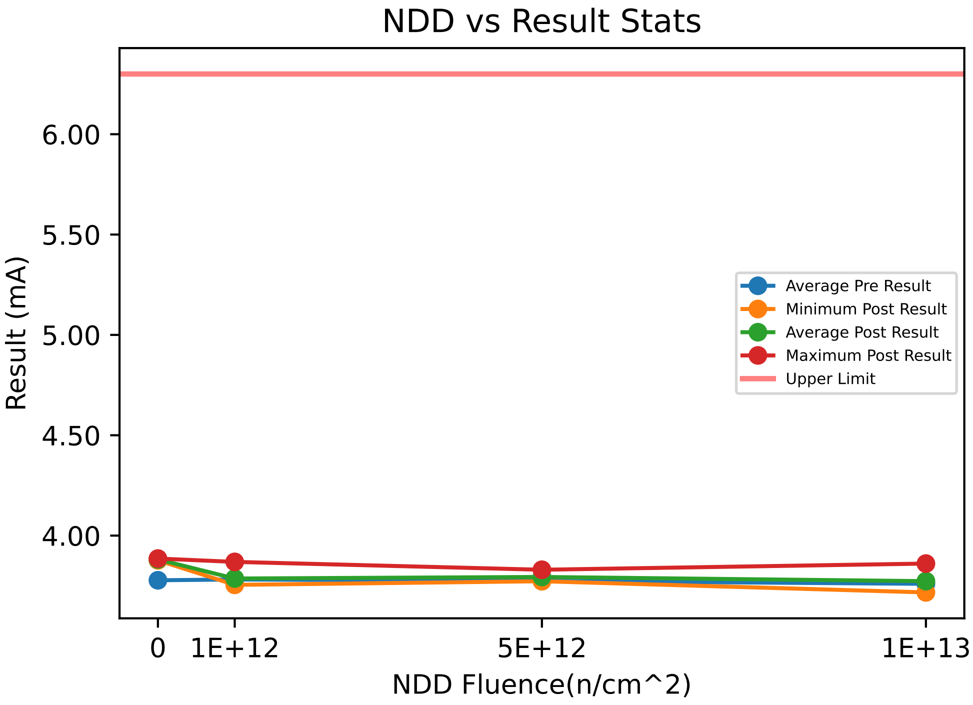
Test Results (Upper Limit = 15.0 (mA))

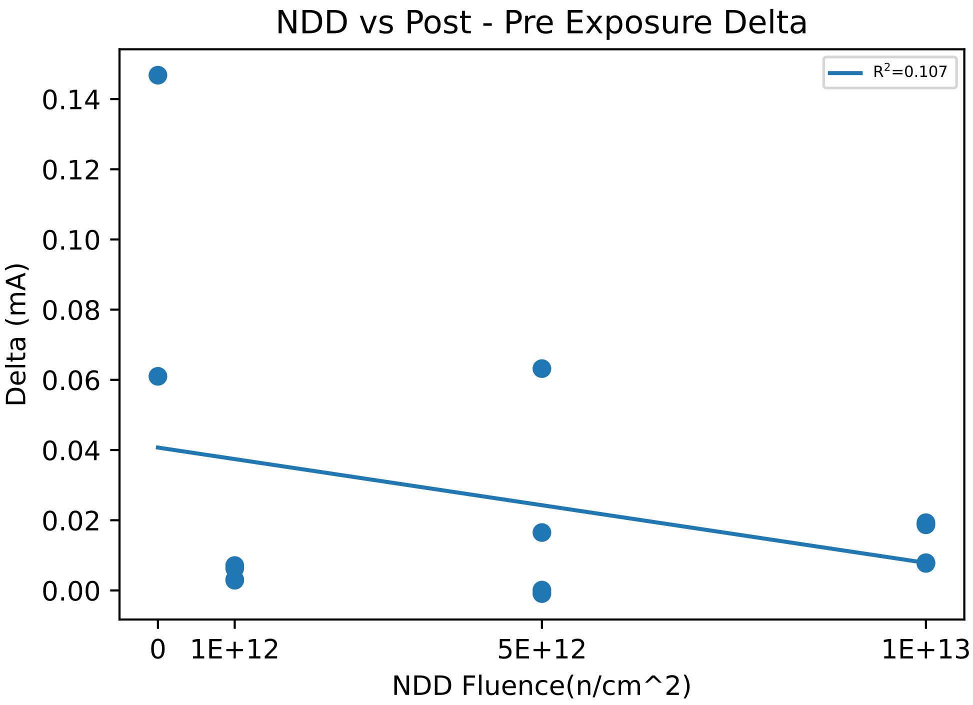
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	12.541	12.212	-0.3291
2	0	Correlation	12.701	12.357	-0.3444
30	1e+12	NDD unbiased	12.535	12.192	-0.3437
31	1e+12	NDD unbiased	12.608	12.139	-0.469
32	1e+12	NDD unbiased	12.666	12.317	-0.3494
33	1e+12	NDD unbiased	12.53	12.436	-0.0945
44	5e+12	NDD unbiased	12.622	12.224	-0.3974
45	5e+12	NDD unbiased	12.483	12.242	-0.2414
46	5e+12	NDD unbiased	12.601	12.204	-0.3969
47	5e+12	NDD unbiased	12.63	12.26	-0.3704
50	1e+13	NDD unbiased	12.307	12.146	-0.1612
51	1e+13	NDD unbiased	12.552	12.116	-0.4368
52	1e+13	NDD unbiased	12.316	12.177	-0.1395
53	1e+13	NDD unbiased	12.334	12.216	-0.1177

Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	12.541	12.621	12.701	0.11335	12.212	12.285	12.357	0.10253	-0.3444	-0.33675	-0.3291	0.010819
1e+12	12.53	12.585	12.666	0.064924	12.139	12.271	12.436	0.13283	-0.469	-0.31415	-0.0945	0.15742
5e+12	12.483	12.584	12.63	0.068253	12.204	12.233	12.26	0.024115	-0.3974	-0.35153	-0.2414	0.074492
1e+13	12.307	12.378	12.552	0.1171	12.116	12.164	12.216	0.043091	-0.4368	-0.2138	-0.1177	0.14972

Device Test: 36.3 IQ_HS_IIM(_Iq HS BOOT IIM Interlock VIN_12V)





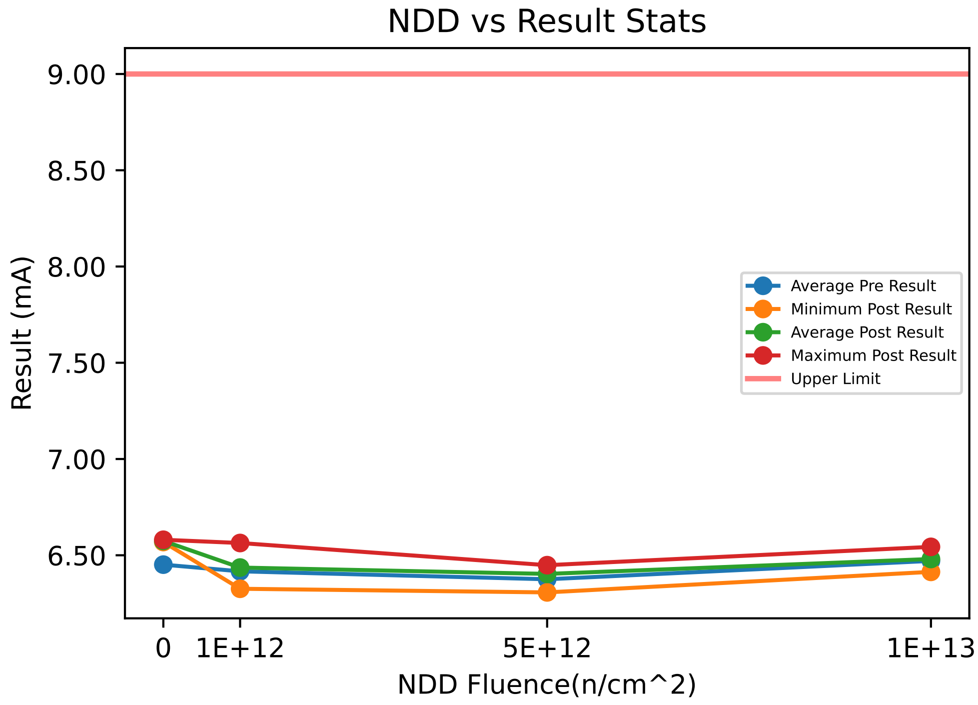
Test Results (Upper Limit = 6.3 (mA))

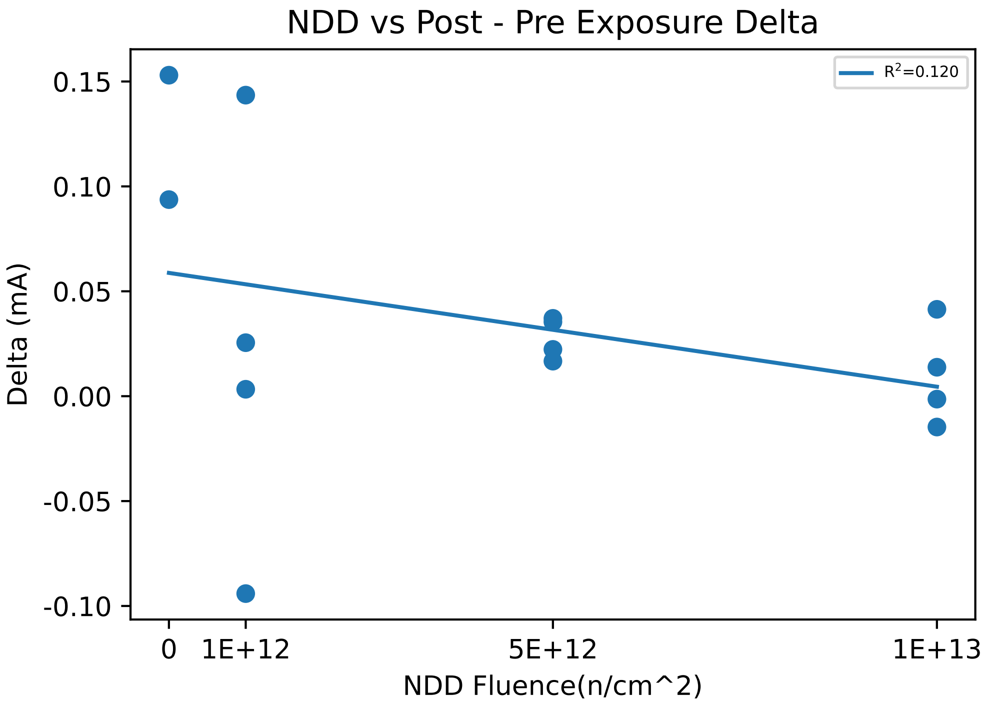
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	3.7389	3.8857	0.1468
2	0	Correlation	3.8159	3.8769	0.061
30	1e+12	NDD unbiased	3.7553	3.7582	0.0029
31	1e+12	NDD unbiased	3.7515	3.7546	0.0031
32	1e+12	NDD unbiased	3.756	3.7631	0.0071
33	1e+12	NDD unbiased	3.8627	3.869	0.0063
44	5e+12	NDD unbiased	3.8308	3.8299	-0.0009
45	5e+12	NDD unbiased	3.7221	3.7853	0.0632
46	5e+12	NDD unbiased	3.7725	3.7726	0.0001
47	5e+12	NDD unbiased	3.7713	3.7878	0.0165
50	1e+13	NDD unbiased	3.7093	3.717	0.0077
51	1e+13	NDD unbiased	3.7592	3.7785	0.0193
52	1e+13	NDD unbiased	3.7171	3.7358	0.0187
53	1e+13	NDD unbiased	3.8527	3.8606	0.0079

Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.7389	3.7774	3.8159	0.054447	3.8769	3.8813	3.8857	0.0062225	0.061	0.1039	0.1468	0.06067
1e+12	3.7515	3.7814	3.8627	0.054253	3.7546	3.7862	3.869	0.055293	0.0029	0.00485	0.0071	0.0021626
5e+12	3.7221	3.7742	3.8308	0.044457	3.7726	3.7939	3.8299	0.024906	-0.0009	0.019725	0.0632	0.030061
1e+13	3.7093	3.7596	3.8527	0.065838	3.717	3.773	3.8606	0.063833	0.0077	0.0134	0.0193	0.0064715

Device Test: 36.6 I_OP_LS_PWM_500KHZ(_Iop LS VIN PWM 500kHz VIN_12V)





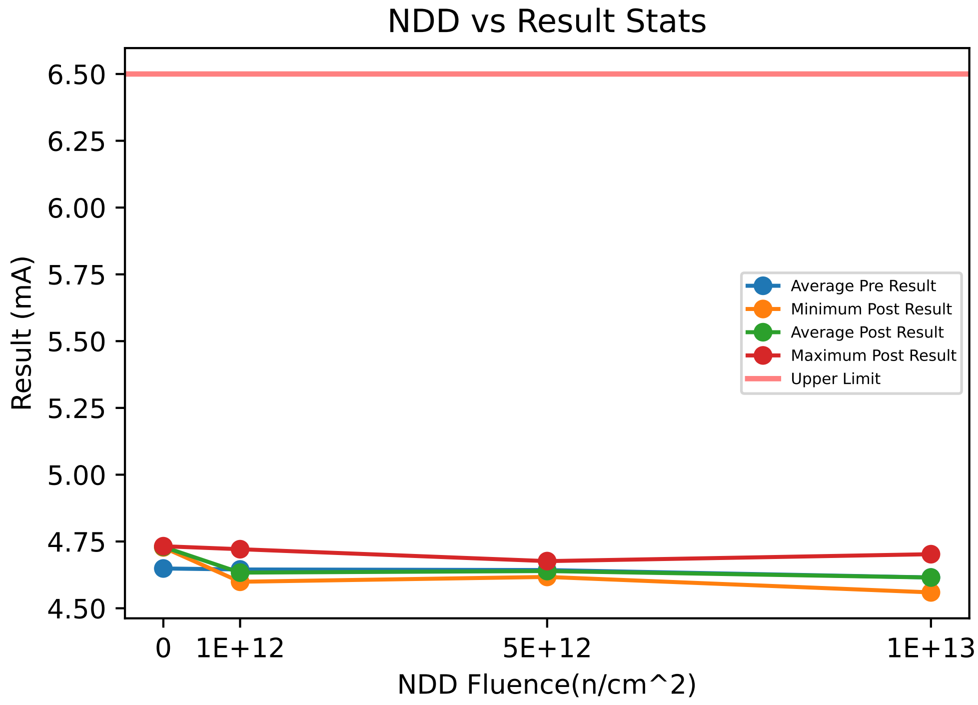
Test Results (Upper Limit = 9.0 (mA))

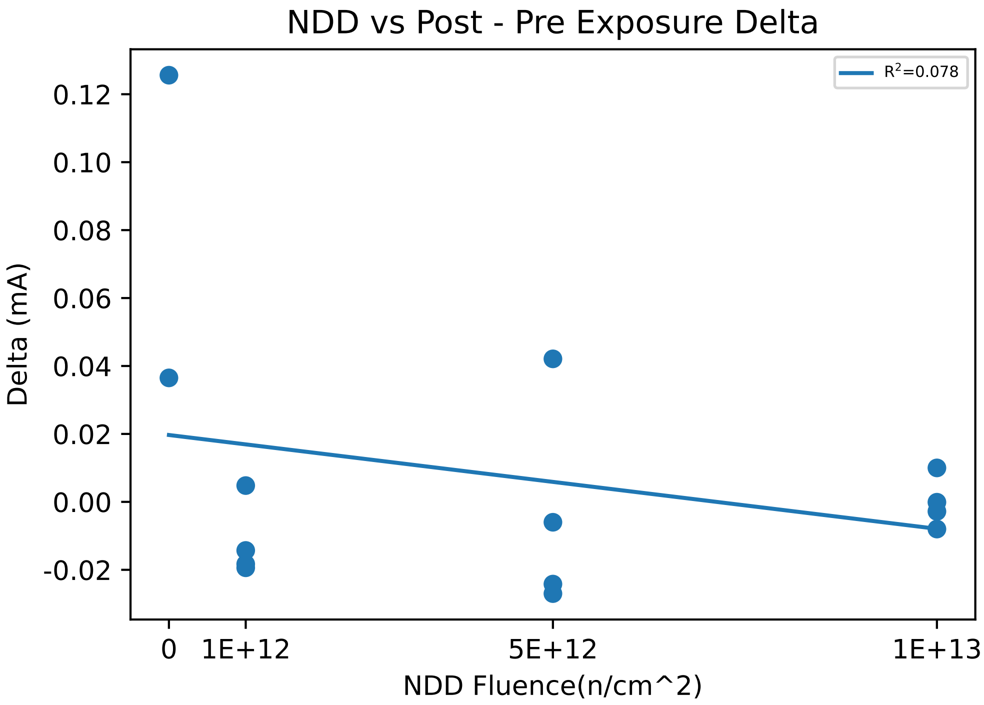
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	6.4158	6.5688	0.153
2	0	Correlation	6.4868	6.5805	0.0937
30	1e+12	NDD unbiased	6.539	6.4449	-0.0941
31	1e+12	NDD unbiased	6.4202	6.5637	0.1435
32	1e+12	NDD unbiased	6.3845	6.41	0.0255
33	1e+12	NDD unbiased	6.3227	6.326	0.0033
44	5e+12	NDD unbiased	6.27	6.3071	0.0371
45	5e+12	NDD unbiased	6.4305	6.4472	0.0167
46	5e+12	NDD unbiased	6.3746	6.41	0.0354
47	5e+12	NDD unbiased	6.4262	6.4485	0.0223
50	1e+13	NDD unbiased	6.5358	6.5211	-0.0147
51	1e+13	NDD unbiased	6.3724	6.4138	0.0414
52	1e+13	NDD unbiased	6.4299	6.4437	0.0138
53	1e+13	NDD unbiased	6.545	6.5436	-0.0014

Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	6.4158	6.4513	6.4868	0.050205	6.5688	6.5747	6.5805	0.0082731	0.0937	0.12335	0.153	0.041931
1e+12	6.3227	6.4166	6.539	0.090999	6.326	6.4361	6.5637	0.098594	-0.0941	0.01955	0.1435	0.097604
5e+12	6.27	6.3753	6.4305	0.074669	6.3071	6.4032	6.4485	0.066507	0.0167	0.027875	0.0371	0.0099614
1e+13	6.3724	6.4708	6.545	0.083837	6.4138	6.4806	6.5436	0.061734	-0.0147	0.009775	0.0414	0.024085

Device Test: 36.7 I_OP_HS_PWM_500KHZ(_Iop HS BOOT PWM 500kHz VIN_12V)





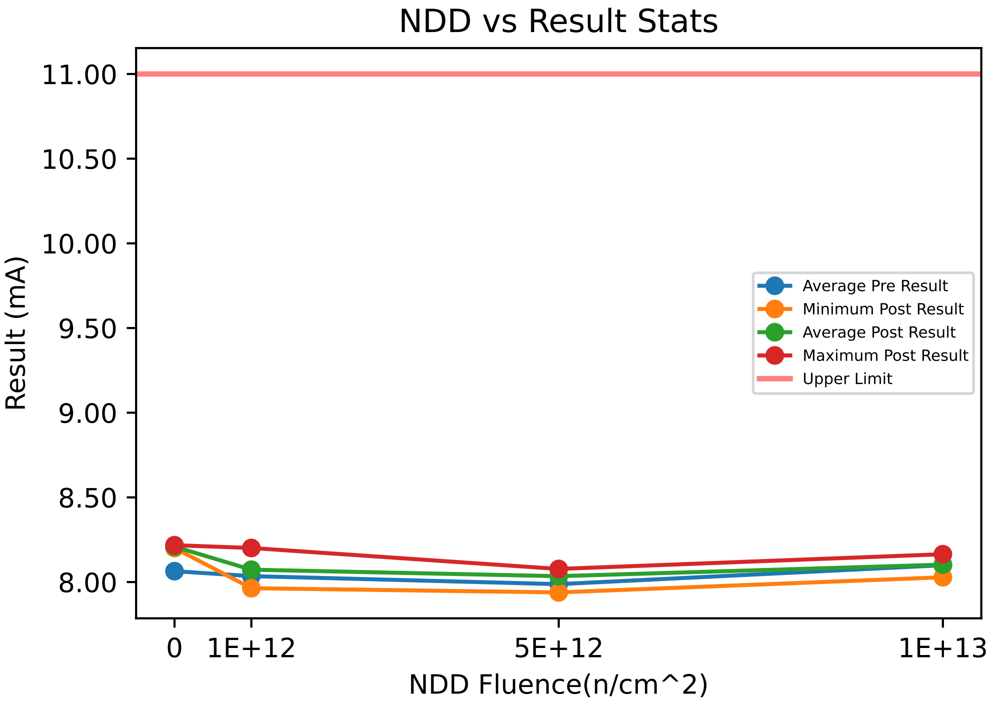
Test Results (Upper Limit = 6.5 (mA))

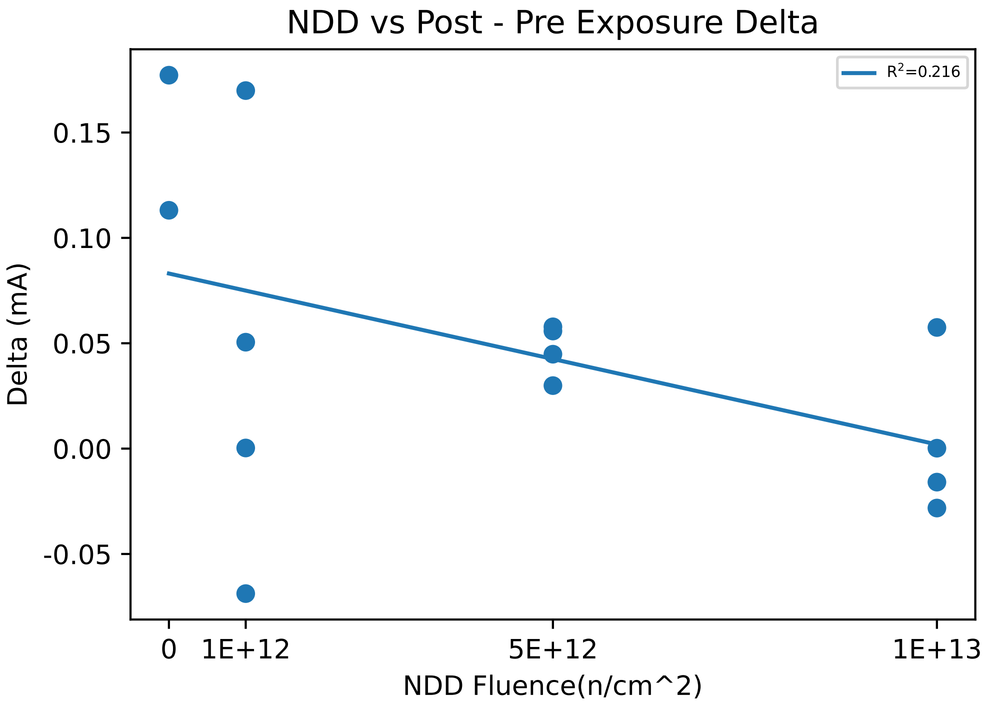
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	4.6067	4.7323	0.1256
2	0	Correlation	4.6912	4.7277	0.0365
30	1e+12	NDD unbiased	4.6209	4.6026	-0.0183
31	1e+12	NDD unbiased	4.6186	4.5992	-0.0194
32	1e+12	NDD unbiased	4.6253	4.611	-0.0143
33	1e+12	NDD unbiased	4.7163	4.7211	0.0048
44	5e+12	NDD unbiased	4.7035	4.6765	-0.027
45	5e+12	NDD unbiased	4.5869	4.629	0.0421
46	5e+12	NDD unbiased	4.6415	4.6173	-0.0242
47	5e+12	NDD unbiased	4.6403	4.6343	-0.006
50	1e+13	NDD unbiased	4.5622	4.5594	-0.0028
51	1e+13	NDD unbiased	4.6261	4.6181	-0.008
52	1e+13	NDD unbiased	4.5704	4.5804	0.01
53	1e+13	NDD unbiased	4.7025	4.7024	-0.0001

Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.6067	4.649	4.6912	0.059751	4.7277	4.73	4.7323	0.0032527	0.0365	0.08105	0.1256	0.063003
1e+12	4.6186	4.6453	4.7163	0.047432	4.5992	4.6335	4.7211	0.058627	-0.0194	-0.0118	0.0048	0.011282
5e+12	4.5869	4.643	4.7035	0.047669	4.6173	4.6393	4.6765	0.025813	-0.027	-0.003775	0.0421	0.031969
1e+13	4.5622	4.6153	4.7025	0.064694	4.5594	4.6151	4.7024	0.063079	-0.008	-0.000225	0.01	0.0075641

Device Test: 36.8 I_OP_LS_PWM_1MHZ(_Iop LS VIN PWM 1MHz VIN_12V)


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

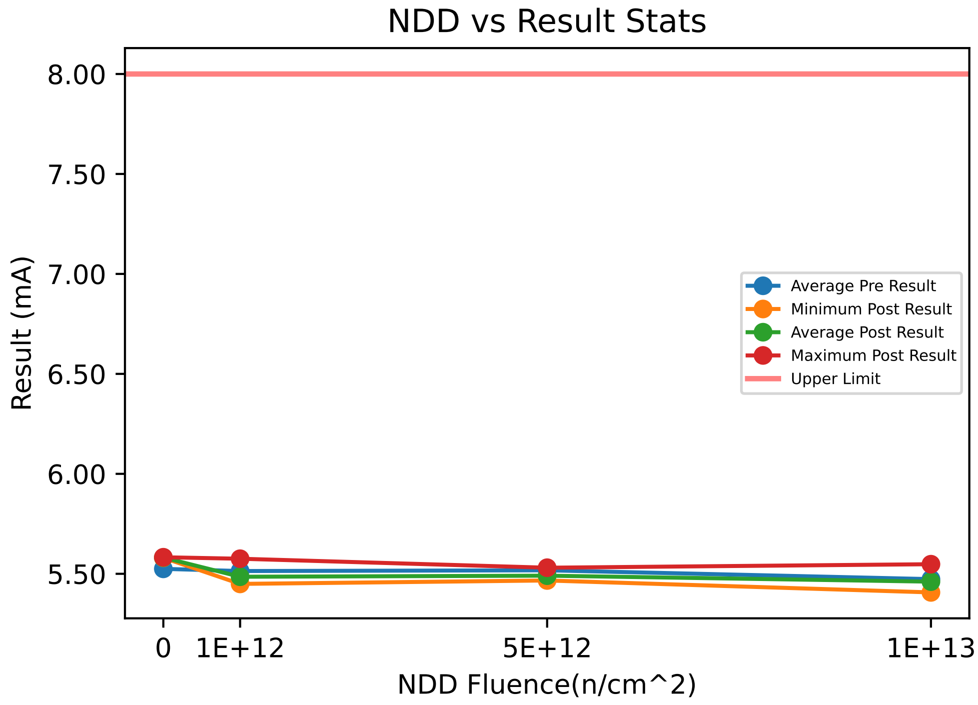
Test Results (Upper Limit = 11.0 (mA))

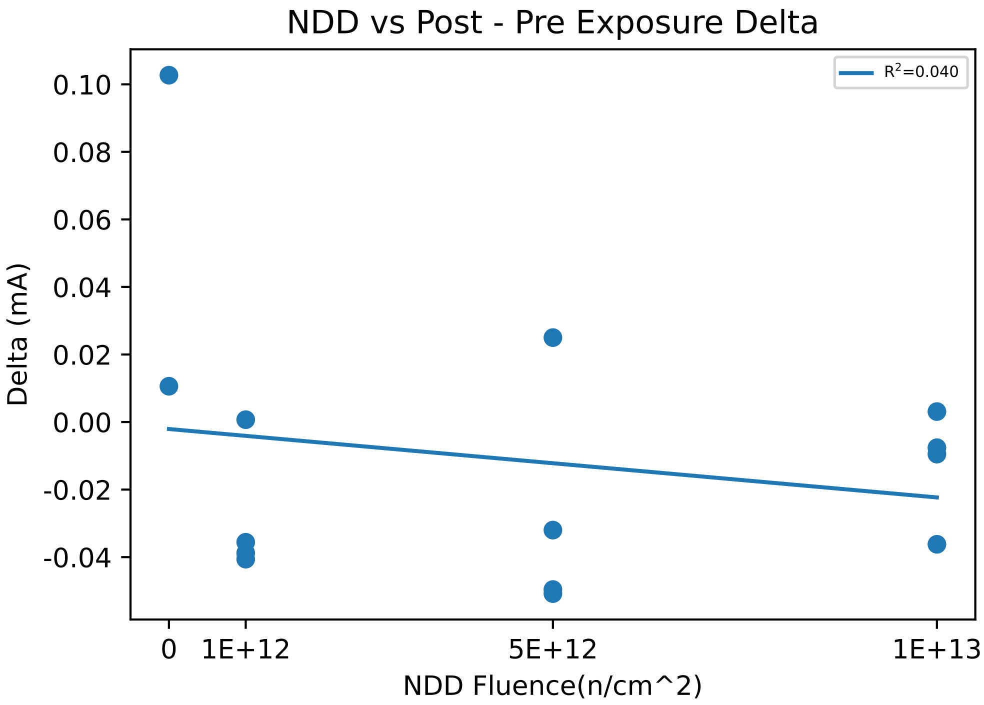
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	8.0238	8.201	0.1772
2	0	Correlation	8.1045	8.2176	0.1131
30	1e+12	NDD unbiased	8.1503	8.0815	-0.0688
31	1e+12	NDD unbiased	8.0313	8.2012	0.1699
32	1e+12	NDD unbiased	7.995	8.0455	0.0505
33	1e+12	NDD unbiased	7.9634	7.9637	0.0003
44	5e+12	NDD unbiased	7.8811	7.9389	0.0578
45	5e+12	NDD unbiased	8.0457	8.0756	0.0299
46	5e+12	NDD unbiased	7.9908	8.0466	0.0558
47	5e+12	NDD unbiased	8.0326	8.0774	0.0448
50	1e+13	NDD unbiased	8.1727	8.1445	-0.0282
51	1e+13	NDD unbiased	7.9707	8.0282	0.0575
52	1e+13	NDD unbiased	8.0737	8.0739	0.0002
53	1e+13	NDD unbiased	8.1803	8.1644	-0.0159

Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	8.0238	8.0641	8.1045	0.057064	8.201	8.2093	8.2176	0.011738	0.1131	0.14515	0.1772	0.045326
1e+12	7.9634	8.035	8.1503	0.08172	7.9637	8.073	8.2012	0.098675	-0.0688	0.037975	0.1699	0.10063
5e+12	7.8811	7.9876	8.0457	0.074729	7.9389	8.0346	8.0774	0.065359	0.0299	0.047075	0.0578	0.012797
1e+13	7.9707	8.0994	8.1803	0.098559	8.0282	8.1028	8.1644	0.063071	-0.0282	0.0034	0.0575	0.037895

Device Test: 36.9 I_OP_HS_PWM_1MHZ(_Iop HS BOOT PWM 1MHz VIN_12V)





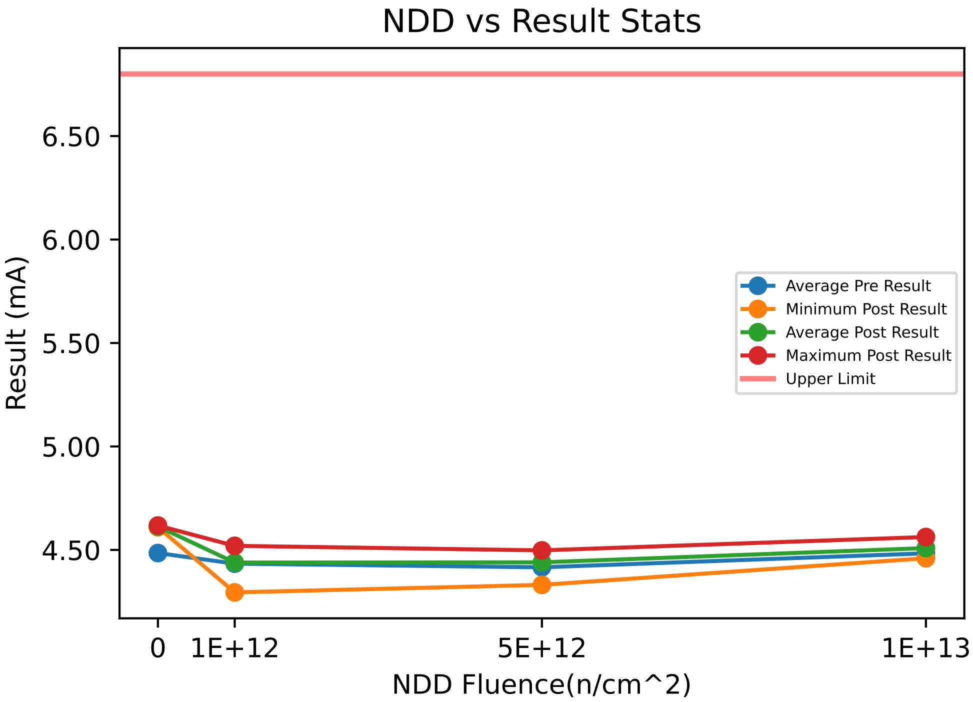
Test Results (Upper Limit = 8.0 (mA))

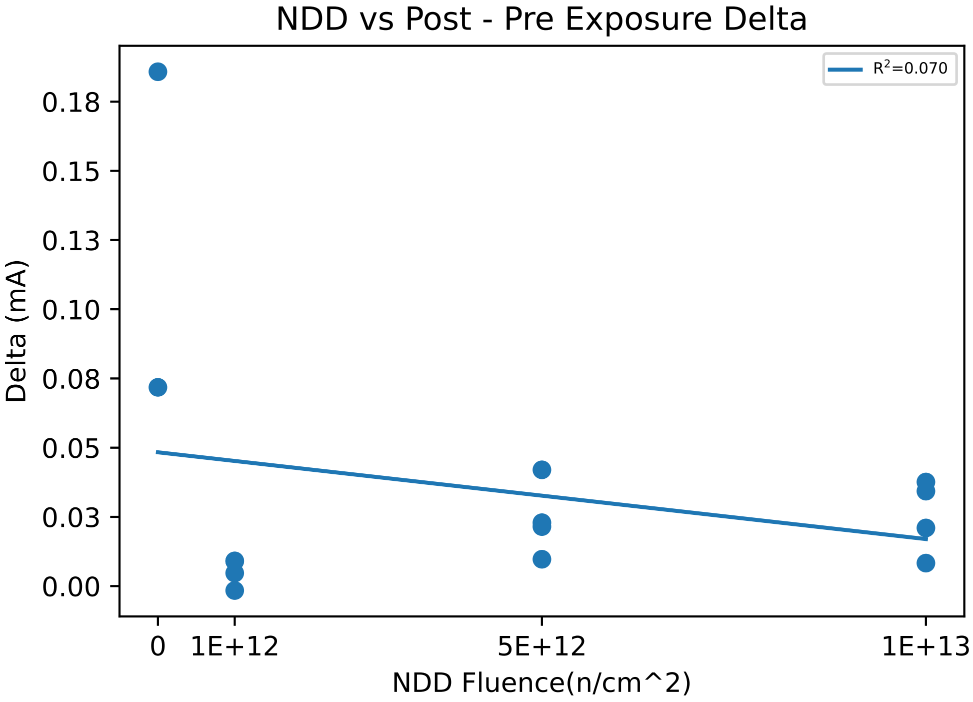
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	5.4801	5.5828	0.1027
2	0	Correlation	5.5695	5.5801	0.0106
30	1e+12	NDD unbiased	5.4905	5.4517	-0.0388
31	1e+12	NDD unbiased	5.4901	5.4495	-0.0406
32	1e+12	NDD unbiased	5.5001	5.4645	-0.0356
33	1e+12	NDD unbiased	5.5747	5.5754	0.0007
44	5e+12	NDD unbiased	5.5813	5.5305	-0.0508
45	5e+12	NDD unbiased	5.4564	5.4814	0.025
46	5e+12	NDD unbiased	5.5162	5.4666	-0.0496
47	5e+12	NDD unbiased	5.516	5.484	-0.032
50	1e+13	NDD unbiased	5.4165	5.407	-0.0095
51	1e+13	NDD unbiased	5.4963	5.4601	-0.0362
52	1e+13	NDD unbiased	5.4251	5.4282	0.0031
53	1e+13	NDD unbiased	5.5556	5.548	-0.0076

Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.4801	5.5248	5.5695	0.063215	5.5801	5.5815	5.5828	0.0019092	0.0106	0.05665	0.1027	0.065125
1e+12	5.4901	5.5138	5.5747	0.040829	5.4495	5.4853	5.5754	0.060446	-0.0406	-0.028575	0.0007	0.019626
5e+12	5.4564	5.5175	5.5813	0.051015	5.4666	5.4906	5.5305	0.027666	-0.0508	-0.02685	0.025	0.035619
1e+13	5.4165	5.4734	5.5556	0.065452	5.407	5.4608	5.548	0.062079	-0.0362	-0.01255	0.0031	0.016714

Device Test: 37.0 IQ_LS_PWM(_Iq LS VIN PWM VIN_14V)





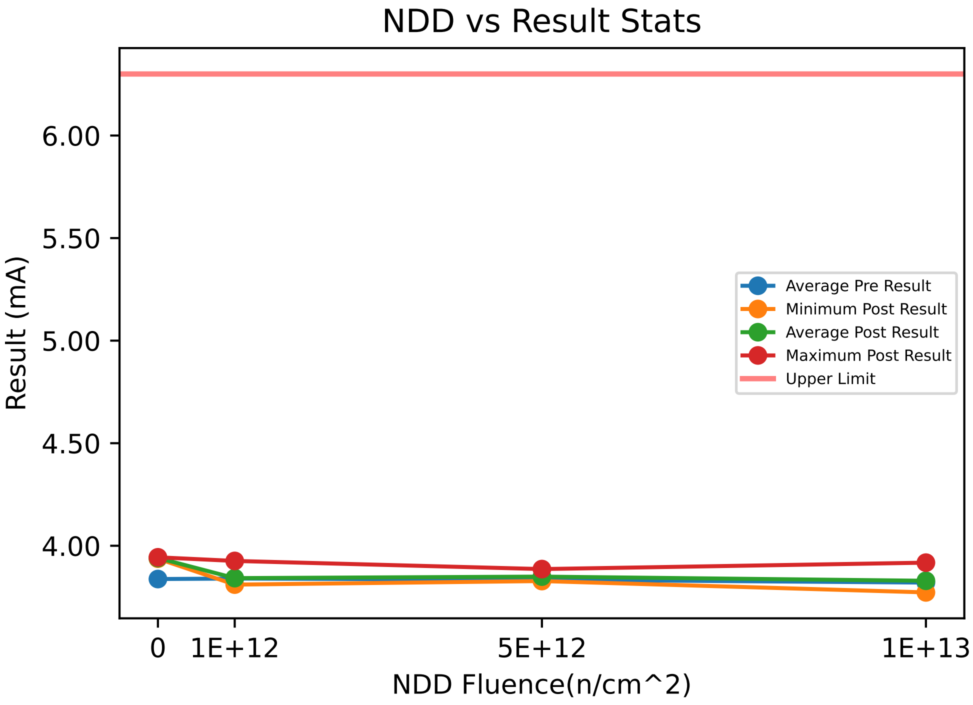
Test Results (Upper Limit = 6.8 (mA))

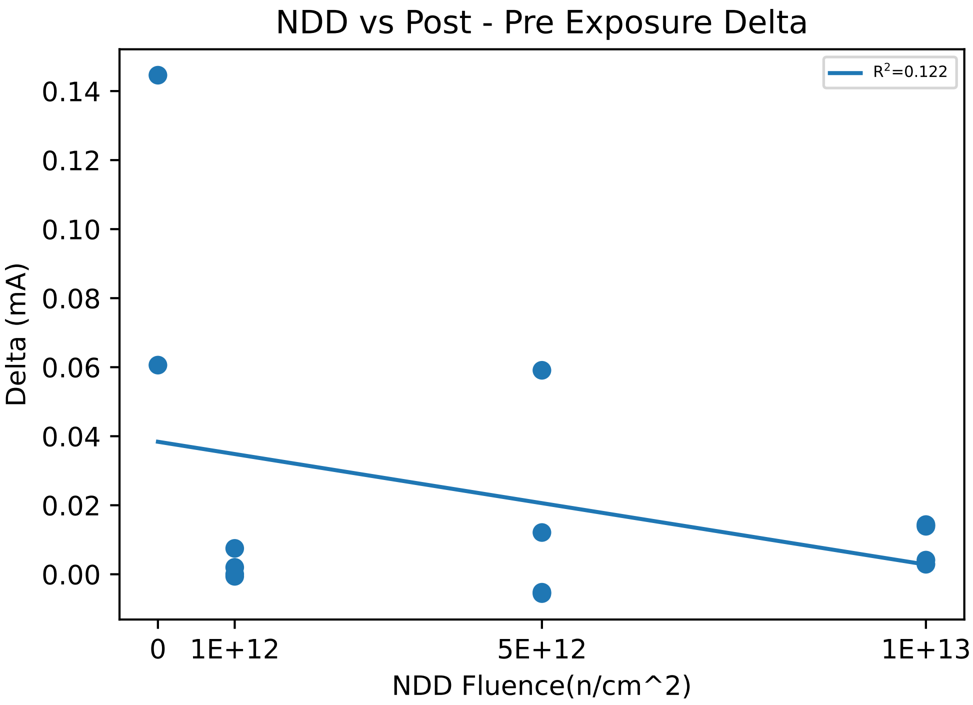
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	4.4321	4.6179	0.1858
2	0	Correlation	4.5378	4.6096	0.0718
30	1e+12	NDD unbiased	4.5107	4.5197	0.009
31	1e+12	NDD unbiased	4.5157	4.5141	-0.0016
32	1e+12	NDD unbiased	4.4224	4.4271	0.0047
33	1e+12	NDD unbiased	4.2856	4.2947	0.0091
44	5e+12	NDD unbiased	4.3081	4.331	0.0229
45	5e+12	NDD unbiased	4.4536	4.4956	0.042
46	5e+12	NDD unbiased	4.4141	4.4356	0.0215
47	5e+12	NDD unbiased	4.4881	4.4978	0.0097
50	1e+13	NDD unbiased	4.4903	4.4986	0.0083
51	1e+13	NDD unbiased	4.5281	4.5624	0.0343
52	1e+13	NDD unbiased	4.4223	4.4599	0.0376
53	1e+13	NDD unbiased	4.4936	4.5146	0.021

Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.4321	4.4849	4.5378	0.074741	4.6096	4.6137	4.6179	0.005869	0.0718	0.1288	0.1858	0.08061
1e+12	4.2856	4.4336	4.5157	0.10757	4.2947	4.4389	4.5197	0.10507	-0.0016	0.0053	0.0091	0.0050365
5e+12	4.3081	4.416	4.4881	0.078013	4.331	4.44	4.4978	0.078172	0.0097	0.024025	0.042	0.013366
1e+13	4.4223	4.4836	4.5281	0.044283	4.4599	4.5089	4.5624	0.042434	0.0083	0.0253	0.0376	0.013414

Device Test: 37.1 IQ_HS_PWM(_Iq HS BOOT PWM VIN_14V)





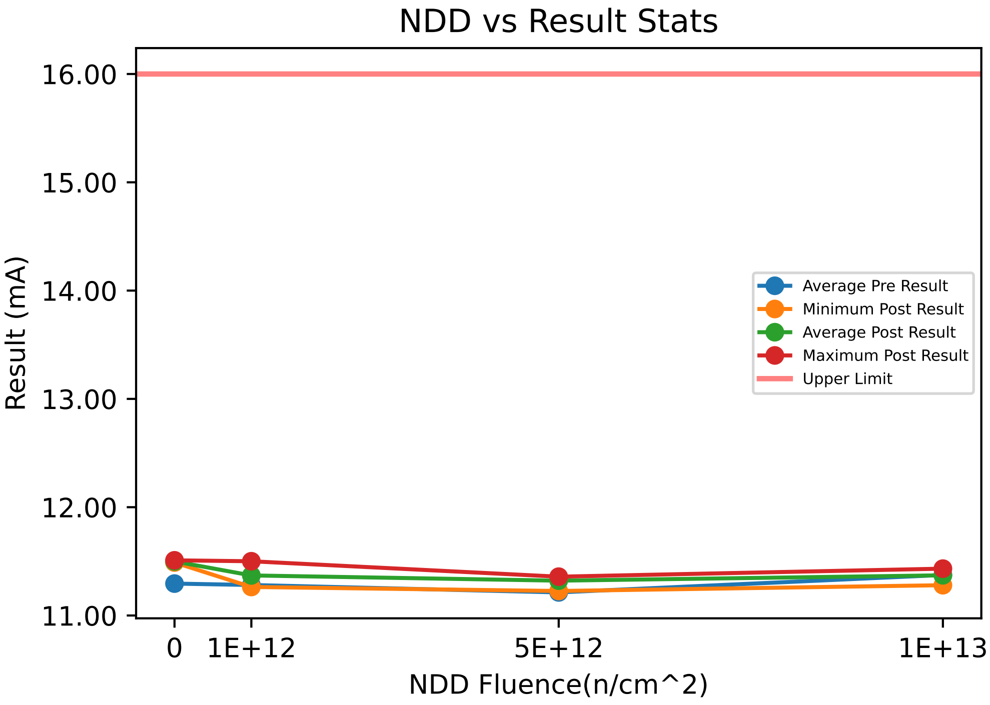
Test Results (Upper Limit = 6.3 (mA))

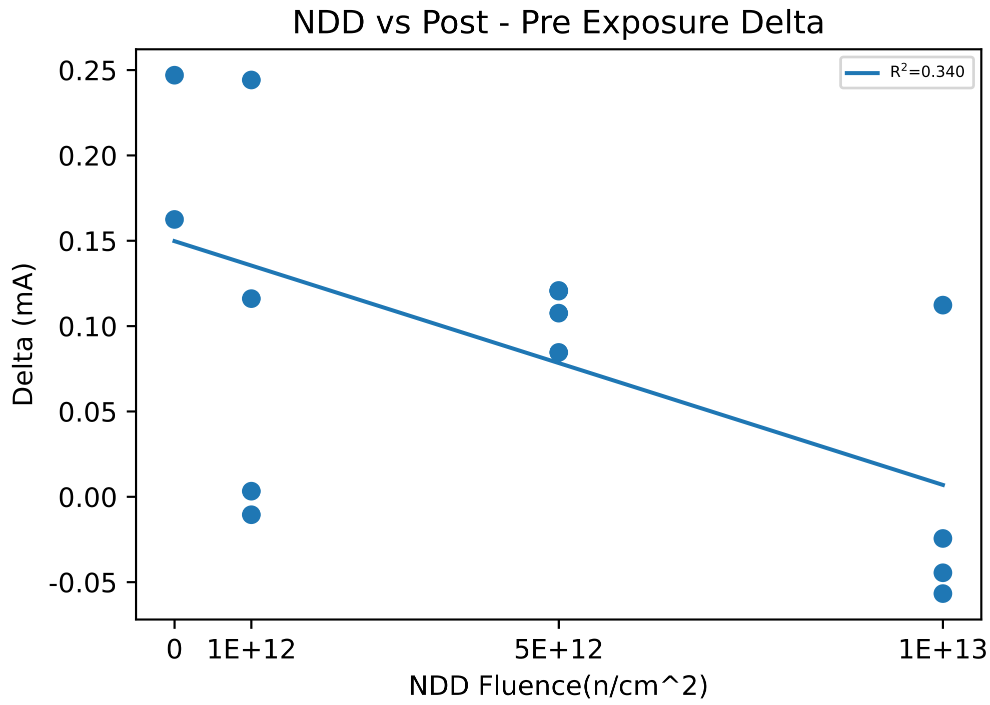
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	3.7991	3.9437	0.1446
2	0	Correlation	3.8764	3.937	0.0606
30	1e+12	NDD unbiased	3.8145	3.8145	0
31	1e+12	NDD unbiased	3.8112	3.8106	-0.0006
32	1e+12	NDD unbiased	3.8159	3.8179	0.002
33	1e+12	NDD unbiased	3.9185	3.926	0.0075
44	5e+12	NDD unbiased	3.8919	3.8863	-0.0056
45	5e+12	NDD unbiased	3.7818	3.8409	0.0591
46	5e+12	NDD unbiased	3.8331	3.8279	-0.0052
47	5e+12	NDD unbiased	3.8311	3.8432	0.0121
50	1e+13	NDD unbiased	3.7697	3.7726	0.0029
51	1e+13	NDD unbiased	3.8195	3.8339	0.0144
52	1e+13	NDD unbiased	3.779	3.7929	0.0139
53	1e+13	NDD unbiased	3.9135	3.9176	0.0041

Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.7991	3.8377	3.8764	0.054659	3.937	3.9404	3.9437	0.0047376	0.0606	0.1026	0.1446	0.059397
1e+12	3.8112	3.84	3.9185	0.052354	3.8106	3.8422	3.926	0.055913	-0.0006	0.002225	0.0075	0.0036882
5e+12	3.7818	3.8345	3.8919	0.045039	3.8279	3.8496	3.8863	0.025393	-0.0056	0.0151	0.0591	0.030472
1e+13	3.7697	3.8204	3.9135	0.065709	3.7726	3.8293	3.9176	0.064182	0.0029	0.008825	0.0144	0.0061716

Device Test: 37.10 I_OP_LS_PWM_2MHZ(_Iop LS VIN PWM 2MHz VIN_14V)





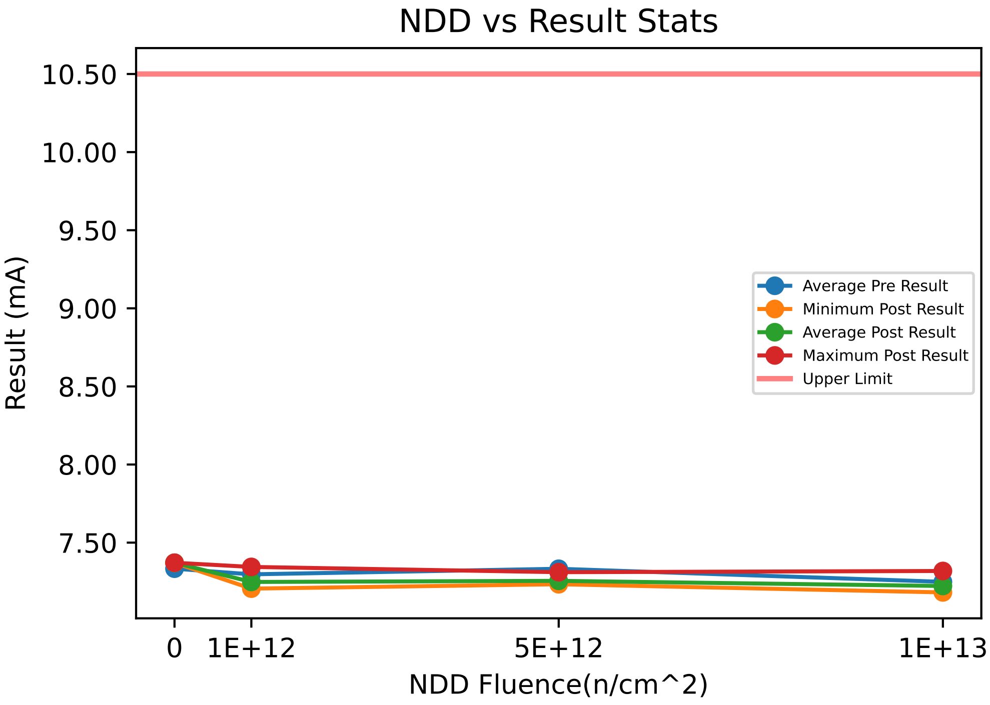
Test Results (Upper Limit = 16.0 (mA))

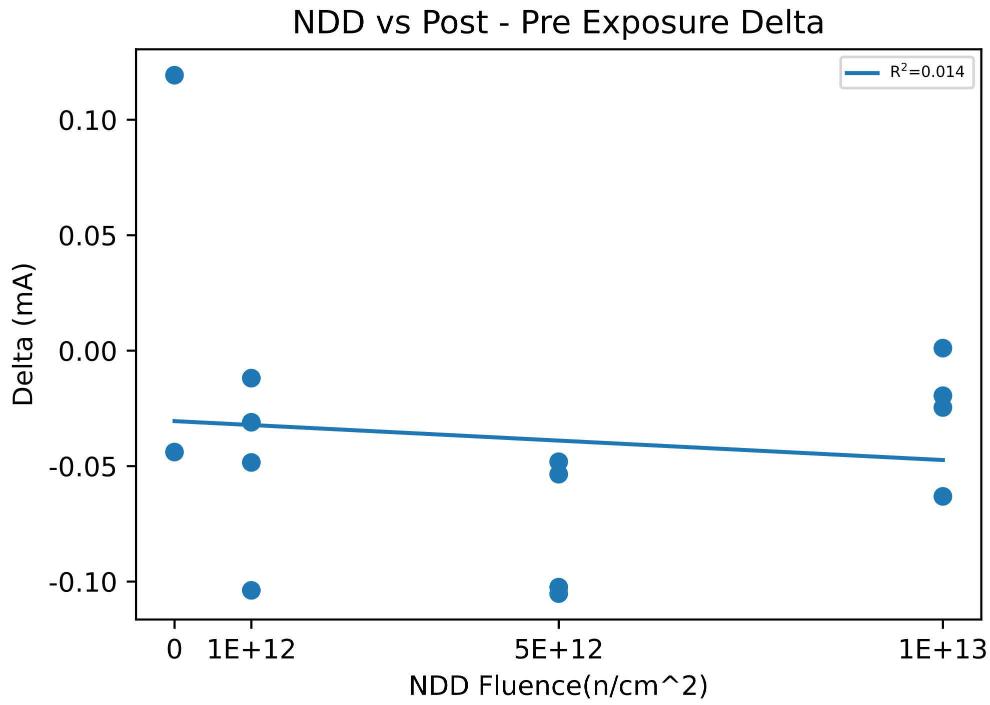
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	11.242	11.489	0.247
2	0	Correlation	11.347	11.509	0.1625
30	1e+12	NDD unbiased	11.374	11.377	0.0033
31	1e+12	NDD unbiased	11.257	11.501	0.2442
32	1e+12	NDD unbiased	11.223	11.339	0.1161
33	1e+12	NDD unbiased	11.274	11.263	-0.0105
44	5e+12	NDD unbiased	11.106	11.226	0.1205
45	5e+12	NDD unbiased	11.273	11.357	0.0846
46	5e+12	NDD unbiased	11.224	11.345	0.1209
47	5e+12	NDD unbiased	11.251	11.358	0.1076
50	1e+13	NDD unbiased	11.471	11.414	-0.0567
51	1e+13	NDD unbiased	11.167	11.28	0.1123
52	1e+13	NDD unbiased	11.382	11.357	-0.0244
53	1e+13	NDD unbiased	11.477	11.433	-0.0445

Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	11.242	11.295	11.347	0.073963	11.489	11.499	11.509	0.014213	0.1625	0.20475	0.247	0.059751
1e+12	11.223	11.282	11.374	0.064917	11.263	11.37	11.501	0.099209	-0.0105	0.088275	0.2442	0.11841
5e+12	11.106	11.213	11.273	0.074406	11.226	11.322	11.358	0.063881	0.0846	0.1084	0.1209	0.017027
1e+13	11.167	11.374	11.477	0.14466	11.28	11.371	11.433	0.068795	-0.0567	-0.003325	0.1123	0.078225

Device Test: 37.11 I_OP_HS_PWM_2MHZ(_Iop HS BOOT PWM 2MHz VIN_14V)


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

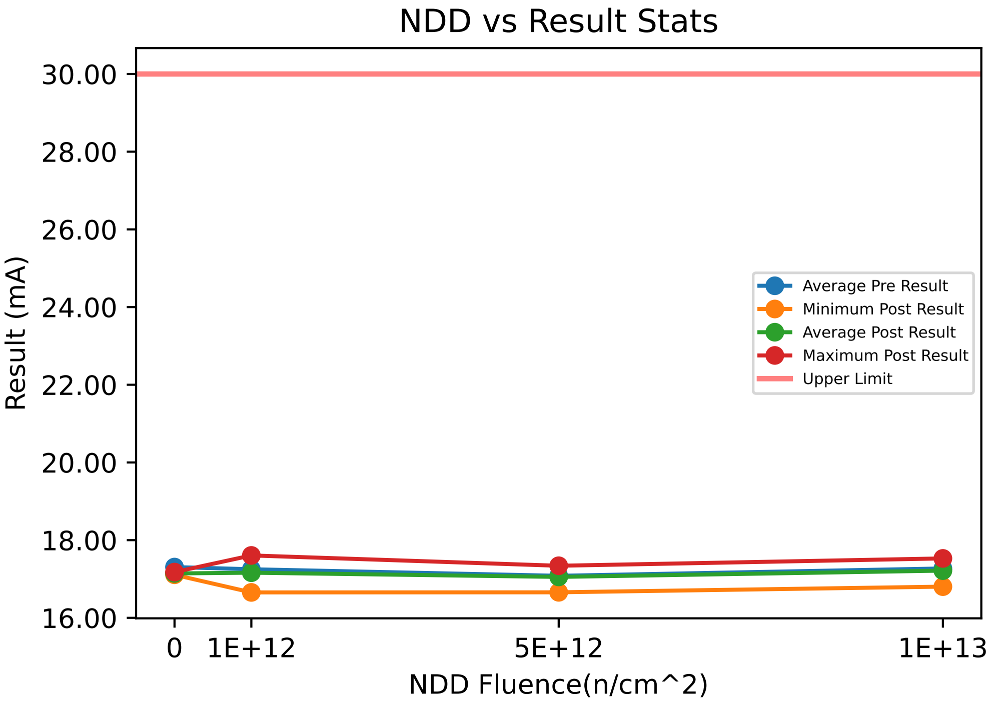
Test Results (Upper Limit = 10.5 (mA))

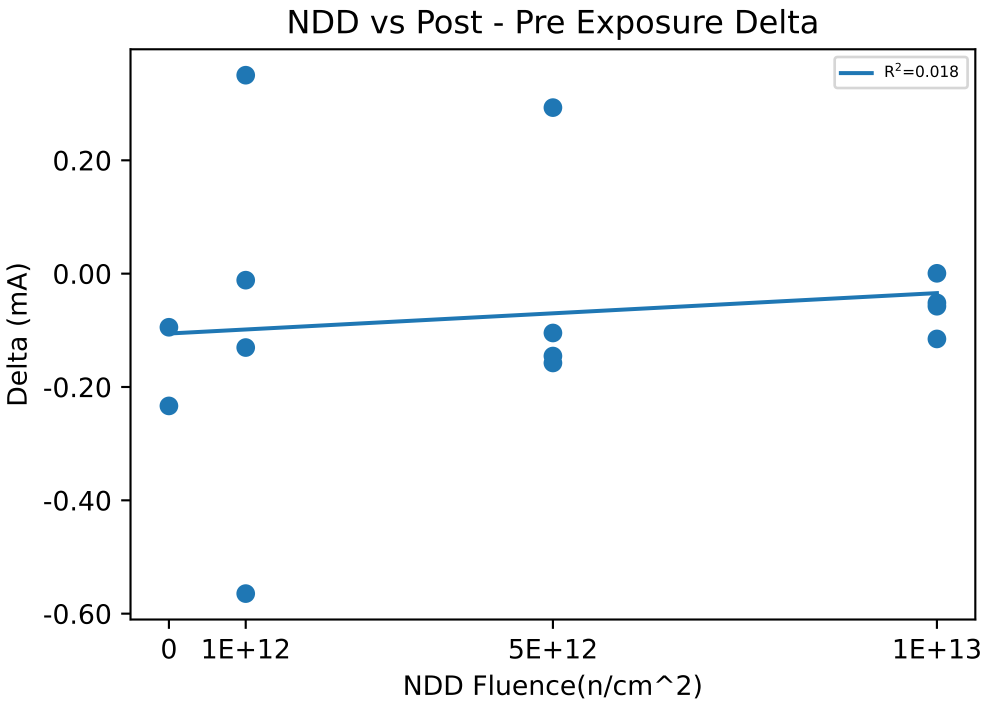
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	7.252	7.3713	0.1193
2	0	Correlation	7.4146	7.3707	-0.0439
30	1e+12	NDD unbiased	7.2611	7.2301	-0.031
31	1e+12	NDD unbiased	7.3094	7.2056	-0.1038
32	1e+12	NDD unbiased	7.2613	7.2129	-0.0484
33	1e+12	NDD unbiased	7.3564	7.3445	-0.0119
44	5e+12	NDD unbiased	7.416	7.3108	-0.1052
45	5e+12	NDD unbiased	7.2817	7.2336	-0.0481
46	5e+12	NDD unbiased	7.3439	7.2415	-0.1024
47	5e+12	NDD unbiased	7.289	7.2355	-0.0535
50	1e+13	NDD unbiased	7.206	7.1814	-0.0246
51	1e+13	NDD unbiased	7.2636	7.2005	-0.0631
52	1e+13	NDD unbiased	7.1884	7.1895	0.0011
53	1e+13	NDD unbiased	7.338	7.3185	-0.0195

Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	7.252	7.3333	7.4146	0.11498	7.3707	7.371	7.3713	0.00042426	-0.0439	0.0377	0.1193	0.1154
1e+12	7.2611	7.2971	7.3564	0.045627	7.2056	7.2483	7.3445	0.064967	-0.1038	-0.048775	-0.0119	0.039596
5e+12	7.2817	7.3327	7.416	0.062116	7.2336	7.2553	7.3108	0.03712	-0.1052	-0.0773	-0.0481	0.0307
1e+13	7.1884	7.249	7.338	0.067467	7.1814	7.2225	7.3185	0.064493	-0.0631	-0.026525	0.0011	0.026795

Device Test: 37.12 I_OP_LS_PWM_5MHZ(_Iop LS VIN PWM 5MHz VIN_14V)





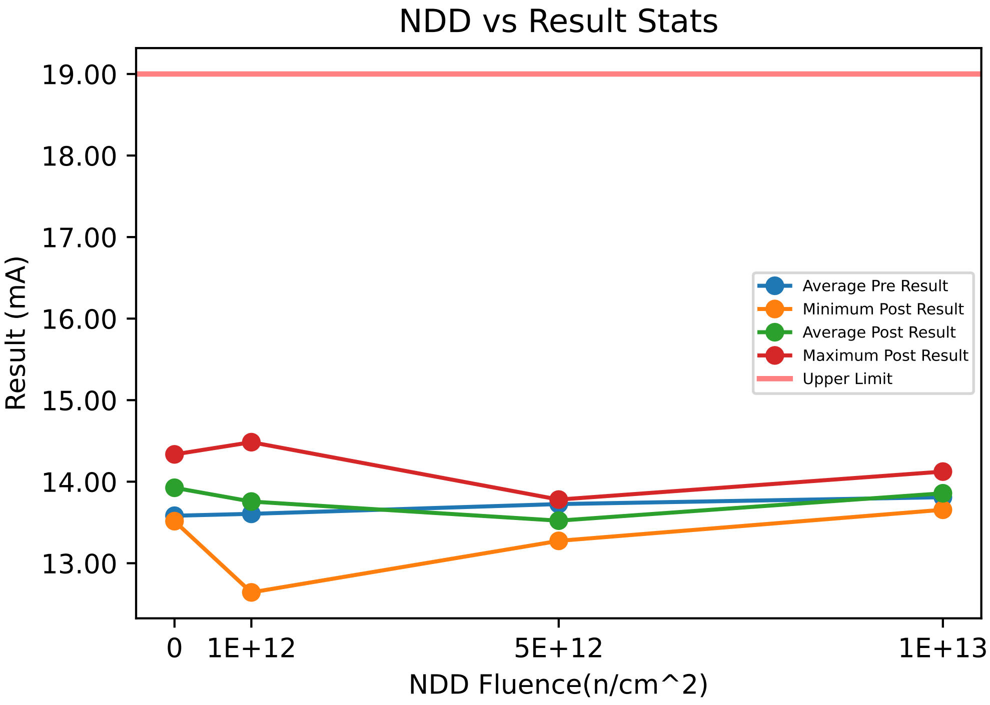
Test Results (Upper Limit = 30.0 (mA))

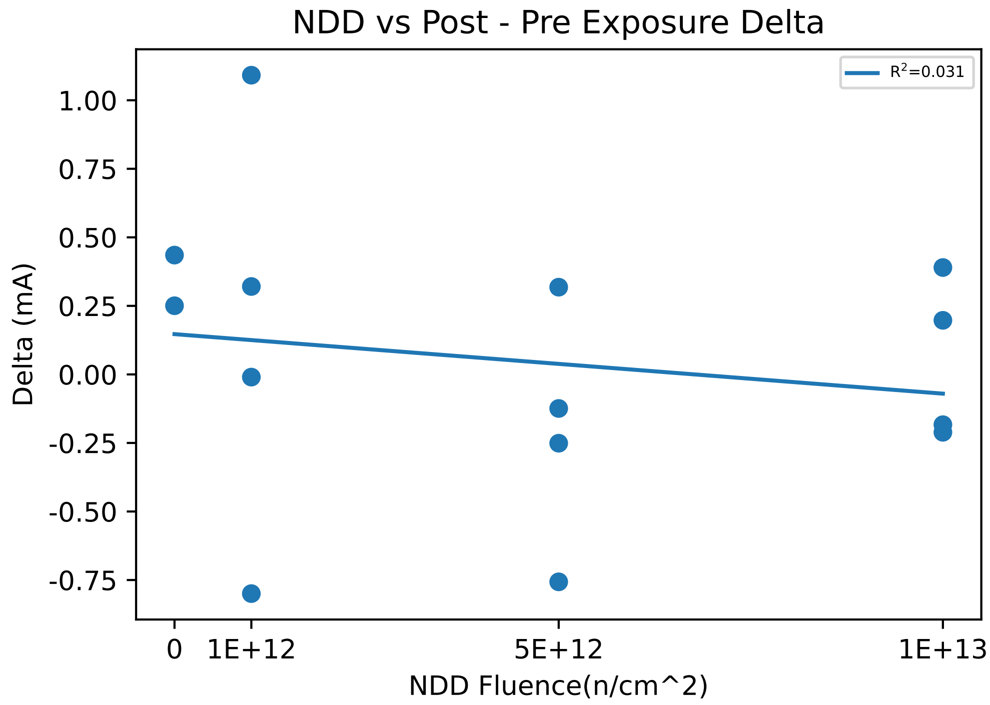
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	17.342	17.108	-0.2334
2	0	Correlation	17.272	17.178	-0.0946
30	1e+12	NDD unbiased	17.729	17.164	-0.5646
31	1e+12	NDD unbiased	17.256	17.607	0.3502
32	1e+12	NDD unbiased	17.351	17.221	-0.1304
33	1e+12	NDD unbiased	16.666	16.655	-0.0115
44	5e+12	NDD unbiased	16.762	16.657	-0.1047
45	5e+12	NDD unbiased	17.048	17.341	0.293
46	5e+12	NDD unbiased	17.022	16.876	-0.1454
47	5e+12	NDD unbiased	17.498	17.341	-0.1576
50	1e+13	NDD unbiased	16.855	16.803	-0.0516
51	1e+13	NDD unbiased	17.645	17.53	-0.1152
52	1e+13	NDD unbiased	17.361	17.361	0.0006
53	1e+13	NDD unbiased	17.225	17.167	-0.0575

Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	17.272	17.307	17.342	0.049002	17.108	17.143	17.178	0.049144	-0.2334	-0.164	-0.0946	0.098146
1e+12	16.666	17.251	17.729	0.43975	16.655	17.162	17.607	0.39077	-0.5646	-0.089075	0.3502	0.37719
5e+12	16.762	17.082	17.498	0.30584	16.657	17.054	17.341	0.34326	-0.1576	-0.028675	0.293	0.21564
1e+13	16.855	17.271	17.645	0.32831	16.803	17.215	17.53	0.31221	-0.1152	-0.055925	0.0006	0.047363

Device Test: 37.13 I_OP_HS_PWM_5MHZ(_Iop HS BOOT PWM 5MHz VIN_14V)





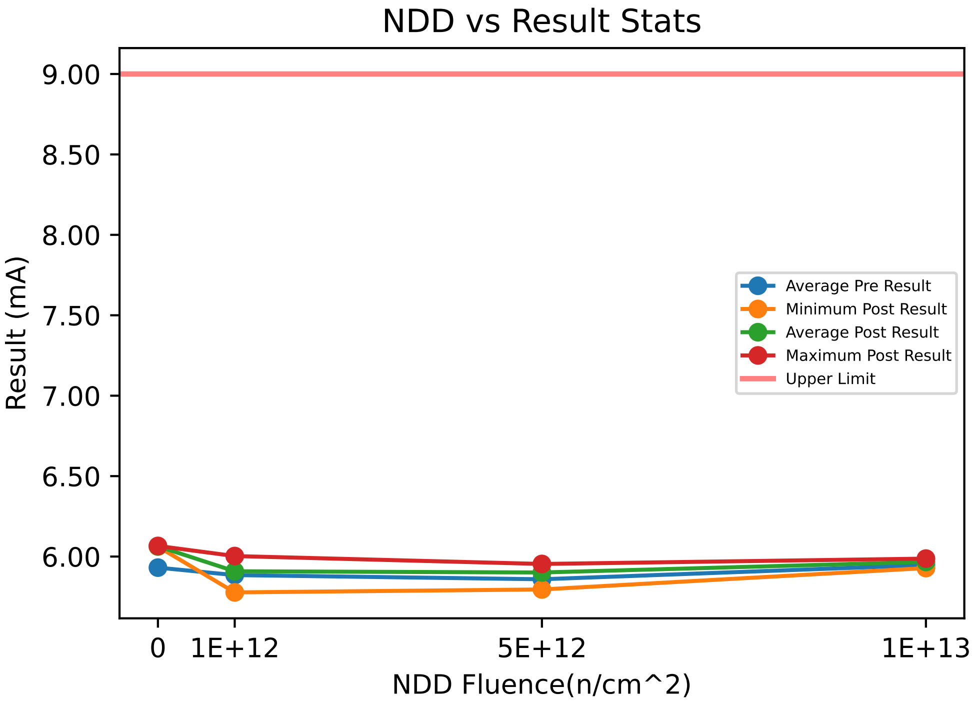
Test Results (Upper Limit = 19.0 (mA))

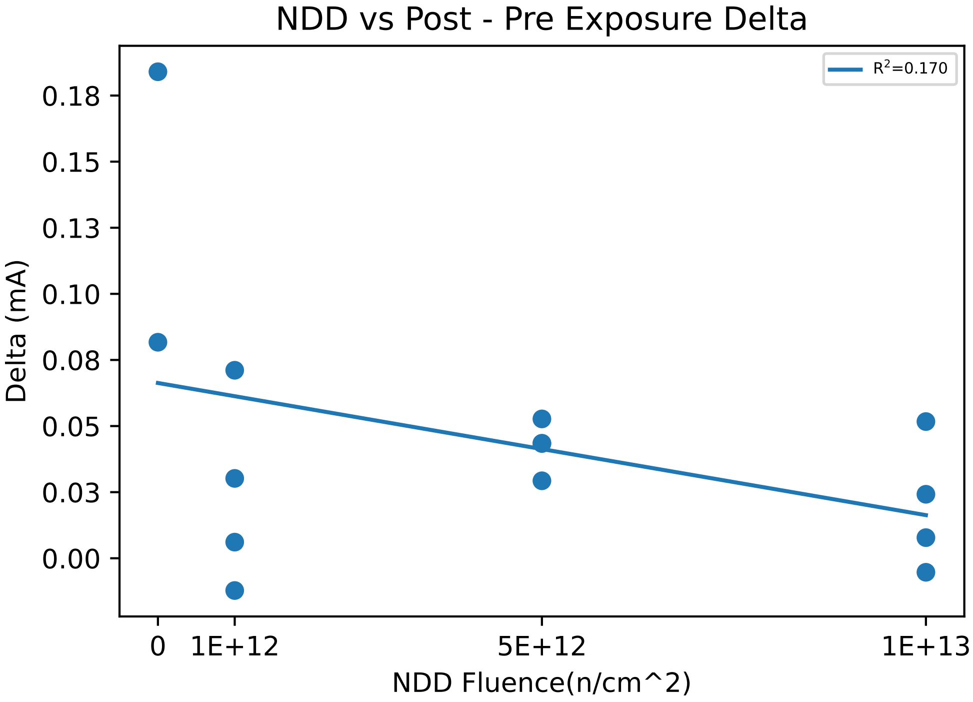
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	13.265	13.516	0.2505
2	0	Correlation	13.899	14.335	0.4352
30	1e+12	NDD unbiased	13.211	14.303	1.0914
31	1e+12	NDD unbiased	14.396	13.597	-0.7995
32	1e+12	NDD unbiased	12.321	12.642	0.3207
33	1e+12	NDD unbiased	14.494	14.484	-0.0098
44	5e+12	NDD unbiased	13.964	13.713	-0.251
45	5e+12	NDD unbiased	14.076	13.32	-0.7566
46	5e+12	NDD unbiased	13.905	13.78	-0.1242
47	5e+12	NDD unbiased	12.956	13.274	0.3182
50	1e+13	NDD unbiased	14.335	14.124	-0.2111
51	1e+13	NDD unbiased	13.313	13.703	0.3899
52	1e+13	NDD unbiased	13.751	13.948	0.1973
53	1e+13	NDD unbiased	13.839	13.656	-0.1834

Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	13.265	13.582	13.899	0.44852	13.516	13.925	14.335	0.57912	0.2505	0.34285	0.4352	0.1306
1e+12	12.321	13.606	14.494	1.0359	12.642	13.756	14.484	0.83577	-0.7995	0.1507	1.0914	0.78368
5e+12	12.956	13.725	14.076	0.5178	13.274	13.522	13.78	0.26196	-0.7566	-0.2034	0.3182	0.4422
1e+13	13.313	13.809	14.335	0.41897	13.656	13.858	14.124	0.2189	-0.2111	0.048175	0.3899	0.29432

Device Test: 37.14 I_OP_LS_IIM_500KHZ(_Iop LS VIN IIM Interlock 500kHz VIN_14V)


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

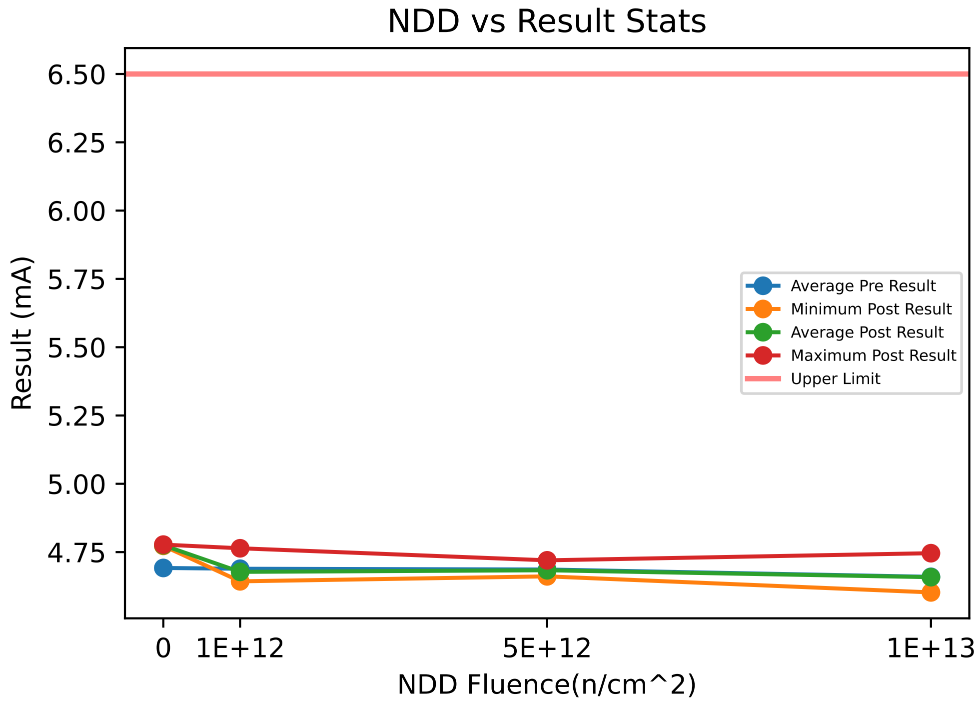
Test Results (Upper Limit = 9.0 (mA))

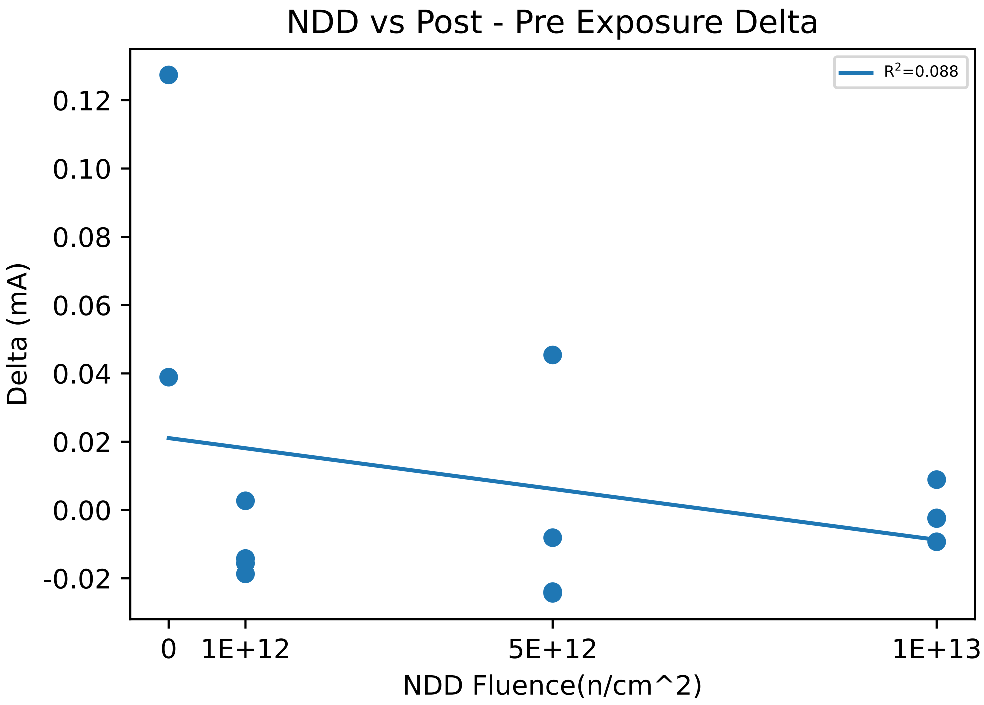
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	5.8819	6.0659	0.184
2	0	Correlation	5.9802	6.0619	0.0817
30	1e+12	NDD unbiased	5.9744	5.9622	-0.0122
31	1e+12	NDD unbiased	5.9319	6.003	0.0711
32	1e+12	NDD unbiased	5.8615	5.8917	0.0302
33	1e+12	NDD unbiased	5.771	5.7771	0.0061
44	5e+12	NDD unbiased	5.7518	5.7953	0.0435
45	5e+12	NDD unbiased	5.8993	5.952	0.0527
46	5e+12	NDD unbiased	5.8591	5.9025	0.0434
47	5e+12	NDD unbiased	5.9246	5.9539	0.0293
50	1e+13	NDD unbiased	5.9783	5.973	-0.0053
51	1e+13	NDD unbiased	5.9252	5.9769	0.0517
52	1e+13	NDD unbiased	5.9042	5.9284	0.0242
53	1e+13	NDD unbiased	5.9793	5.9871	0.0078

Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.8819	5.931	5.9802	0.069509	6.0619	6.0639	6.0659	0.0028284	0.0817	0.13285	0.184	0.072337
1e+12	5.771	5.8847	5.9744	0.088957	5.7771	5.9085	6.003	0.098931	-0.0122	0.0238	0.0711	0.035998
5e+12	5.7518	5.8587	5.9246	0.076199	5.7953	5.9009	5.9539	0.074328	0.0293	0.042225	0.0527	0.0096573
1e+13	5.9042	5.9467	5.9793	0.03799	5.9284	5.9664	5.9871	0.025989	-0.0053	0.0196	0.0517	0.024568

Device Test: 37.15 I_OP_HS_IIM_500KHZ(_Iop HS BOOT IIM Interlock 500kHz VIN_14V)





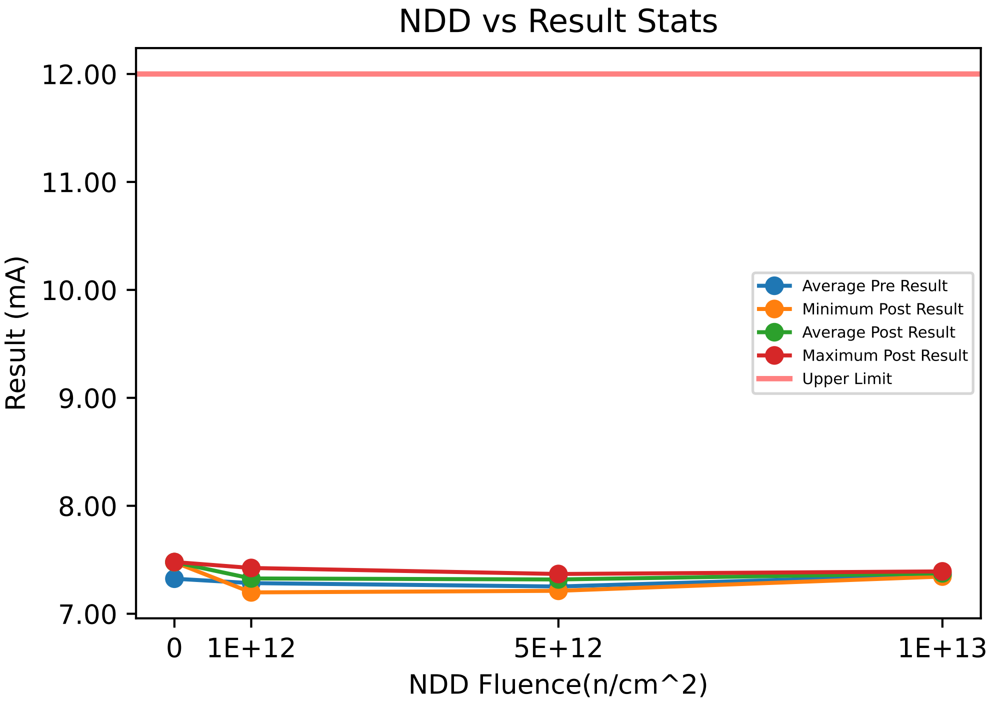
Test Results (Upper Limit = 6.5 (mA))

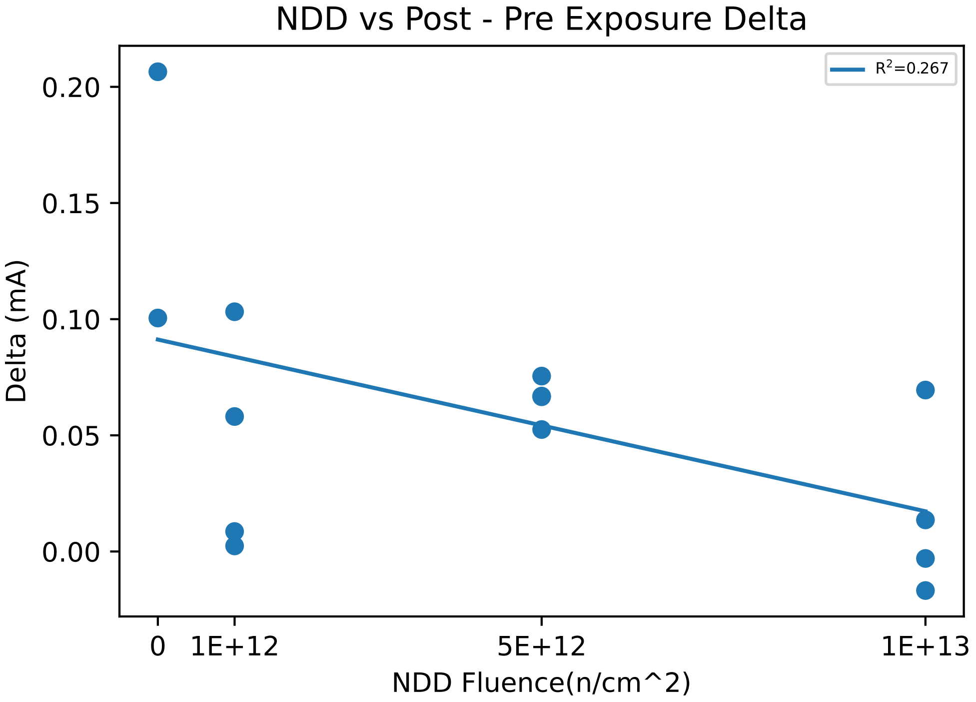
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	4.65	4.7774	0.1274
2	0	Correlation	4.7339	4.7728	0.0389
30	1e+12	NDD unbiased	4.6629	4.6473	-0.0156
31	1e+12	NDD unbiased	4.6617	4.643	-0.0187
32	1e+12	NDD unbiased	4.6704	4.6562	-0.0142
33	1e+12	NDD unbiased	4.7613	4.764	0.0027
44	5e+12	NDD unbiased	4.7438	4.7199	-0.0239
45	5e+12	NDD unbiased	4.6296	4.675	0.0454
46	5e+12	NDD unbiased	4.6856	4.6612	-0.0244
47	5e+12	NDD unbiased	4.6862	4.6781	-0.0081
50	1e+13	NDD unbiased	4.605	4.6025	-0.0025
51	1e+13	NDD unbiased	4.6691	4.6598	-0.0093
52	1e+13	NDD unbiased	4.6156	4.6245	0.0089
53	1e+13	NDD unbiased	4.7483	4.746	-0.0023

Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.65	4.692	4.7339	0.059326	4.7728	4.7751	4.7774	0.0032527	0.0389	0.08315	0.1274	0.062579
1e+12	4.6617	4.6891	4.7613	0.048304	4.643	4.6776	4.764	0.057845	-0.0187	-0.01145	0.0027	0.0096189
5e+12	4.6296	4.6863	4.7438	0.046625	4.6612	4.6836	4.7199	0.025322	-0.0244	-0.00275	0.0454	0.03298
1e+13	4.605	4.6595	4.7483	0.065511	4.6025	4.6582	4.746	0.063113	-0.0093	-0.0013	0.0089	0.0075383

Device Test: 37.16 I_OP_LS_IIM_1MHZ(_Iop LS VIN IIM Interlock 1MHz VIN_14V)


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

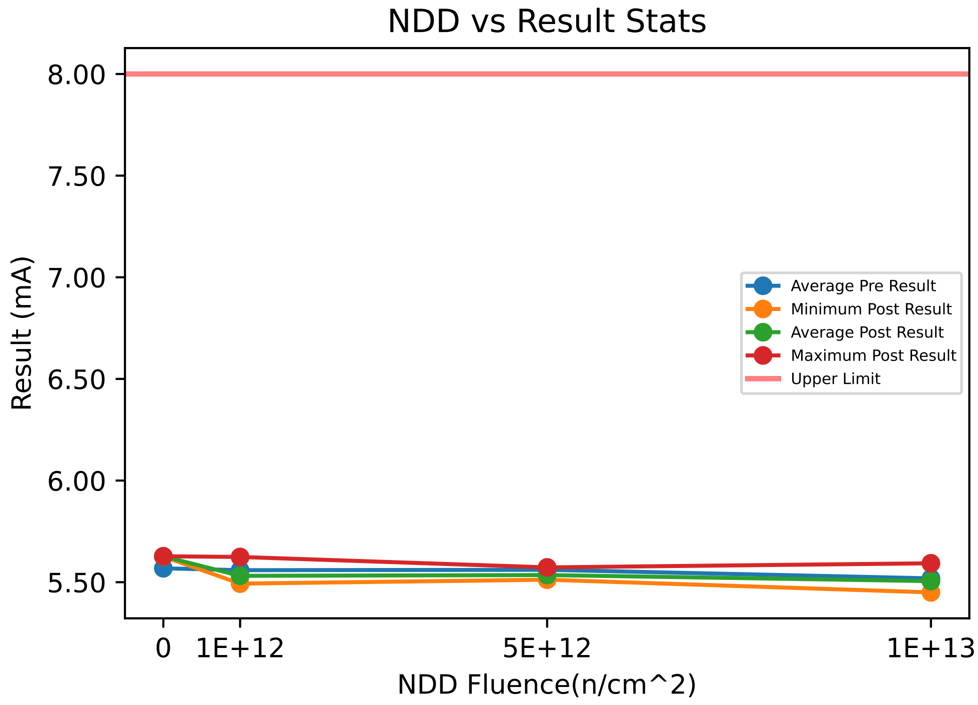
Test Results (Upper Limit = 12.0 (mA))

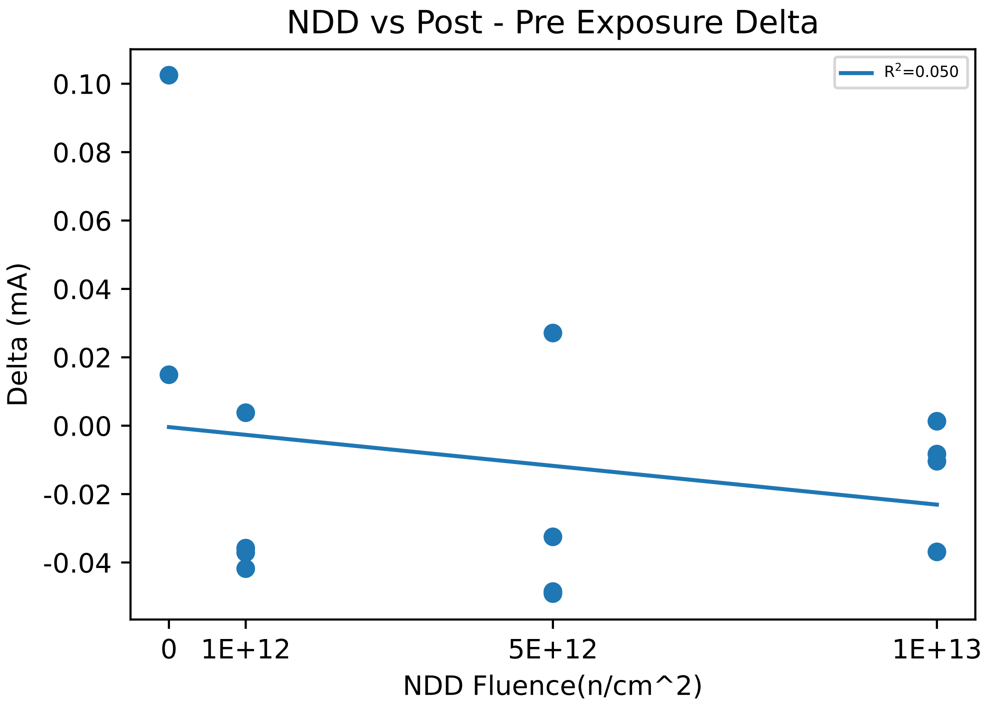
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	7.2728	7.4793	0.2065
2	0	Correlation	7.3765	7.477	0.1005
30	1e+12	NDD unbiased	7.3677	7.3763	0.0086
31	1e+12	NDD unbiased	7.321	7.4242	0.1032
32	1e+12	NDD unbiased	7.2516	7.3097	0.0581
33	1e+12	NDD unbiased	7.1955	7.1979	0.0024
44	5e+12	NDD unbiased	7.146	7.2126	0.0666
45	5e+12	NDD unbiased	7.2917	7.3672	0.0755
46	5e+12	NDD unbiased	7.2561	7.323	0.0669
47	5e+12	NDD unbiased	7.3159	7.3684	0.0525
50	1e+13	NDD unbiased	7.3976	7.3808	-0.0168
51	1e+13	NDD unbiased	7.3104	7.3799	0.0695
52	1e+13	NDD unbiased	7.331	7.3446	0.0136
53	1e+13	NDD unbiased	7.3955	7.3925	-0.003

Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	7.2728	7.3247	7.3765	0.073327	7.477	7.4782	7.4793	0.0016263	0.1005	0.1535	0.2065	0.074953
1e+12	7.1955	7.2839	7.3677	0.075843	7.1979	7.327	7.4242	0.098055	0.0024	0.043075	0.1032	0.047201
5e+12	7.146	7.2524	7.3159	0.075081	7.2126	7.3178	7.3684	0.073246	0.0525	0.065375	0.0755	0.0095238
1e+13	7.3104	7.3586	7.3976	0.0446	7.3446	7.3744	7.3925	0.020711	-0.0168	0.015825	0.0695	0.03788

Device Test: 37.17 I_OP_HS_IIM_1MHZ(_Iop HS BOOT IIM Interlock 1MHz VIN_14V)





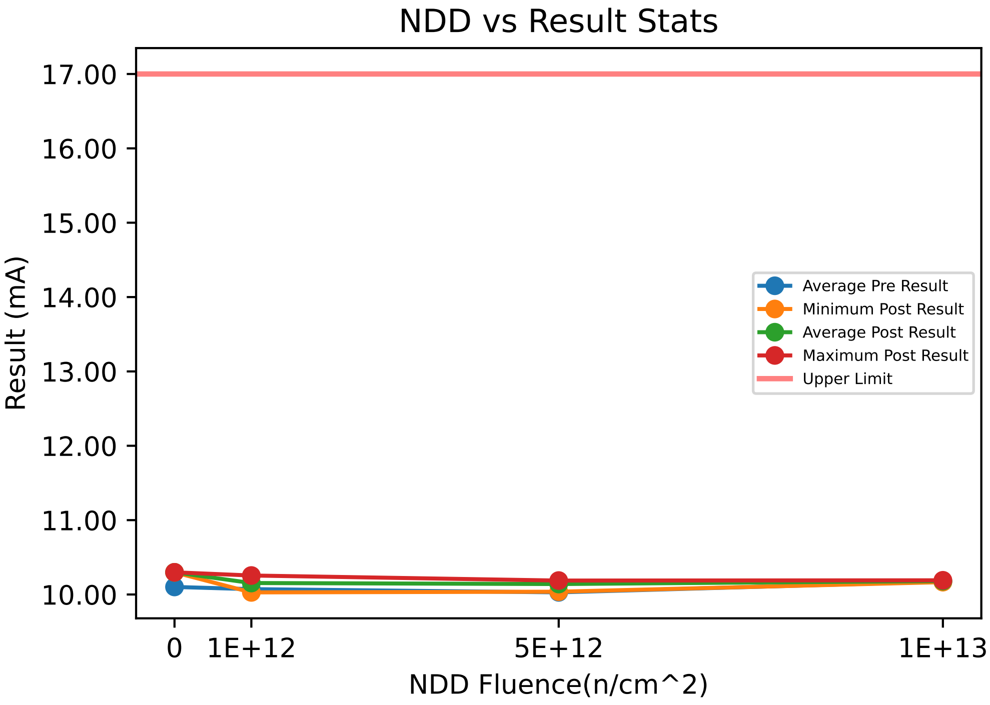
Test Results (Upper Limit = 8.0 (mA))

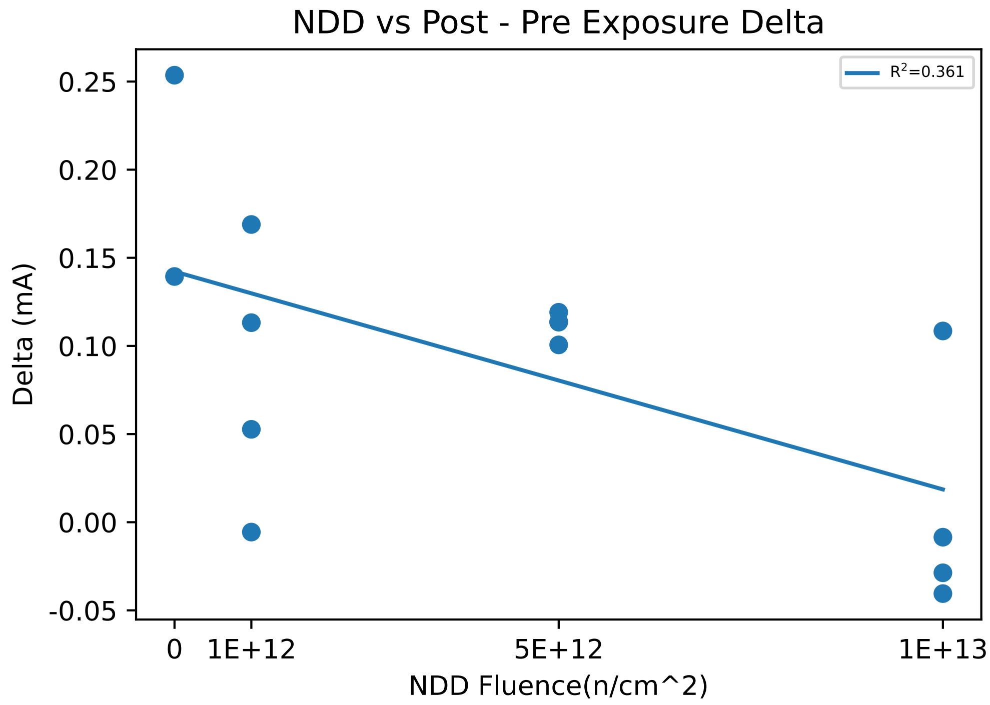
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	5.524	5.6265	0.1025
2	0	Correlation	5.6128	5.6277	0.0149
30	1e+12	NDD unbiased	5.5341	5.497	-0.0371
31	1e+12	NDD unbiased	5.5348	5.493	-0.0418
32	1e+12	NDD unbiased	5.547	5.5112	-0.0358
33	1e+12	NDD unbiased	5.6203	5.6241	0.0038
44	5e+12	NDD unbiased	5.6213	5.5728	-0.0485
45	5e+12	NDD unbiased	5.4991	5.5262	0.0271
46	5e+12	NDD unbiased	5.5613	5.5122	-0.0491
47	5e+12	NDD unbiased	5.5617	5.5292	-0.0325
50	1e+13	NDD unbiased	5.4602	5.4498	-0.0104
51	1e+13	NDD unbiased	5.5429	5.506	-0.0369
52	1e+13	NDD unbiased	5.4711	5.4724	0.0013
53	1e+13	NDD unbiased	5.6013	5.593	-0.0083

Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.524	5.5684	5.6128	0.062791	5.6265	5.6271	5.6277	0.00084853	0.0149	0.0587	0.1025	0.061943
1e+12	5.5341	5.5591	5.6203	0.041261	5.493	5.5313	5.6241	0.062341	-0.0418	-0.027725	0.0038	0.021174
5e+12	5.4991	5.5609	5.6213	0.049894	5.5122	5.5351	5.5728	0.026203	-0.0491	-0.02575	0.0271	0.036062
1e+13	5.4602	5.5189	5.6013	0.066071	5.4498	5.5053	5.593	0.062861	-0.0369	-0.013575	0.0013	0.016363

Device Test: 37.18 I_OP_LS_IIM_2MHZ(_Iop LS VIN IIM Interlock 2MHz VIN_14V)





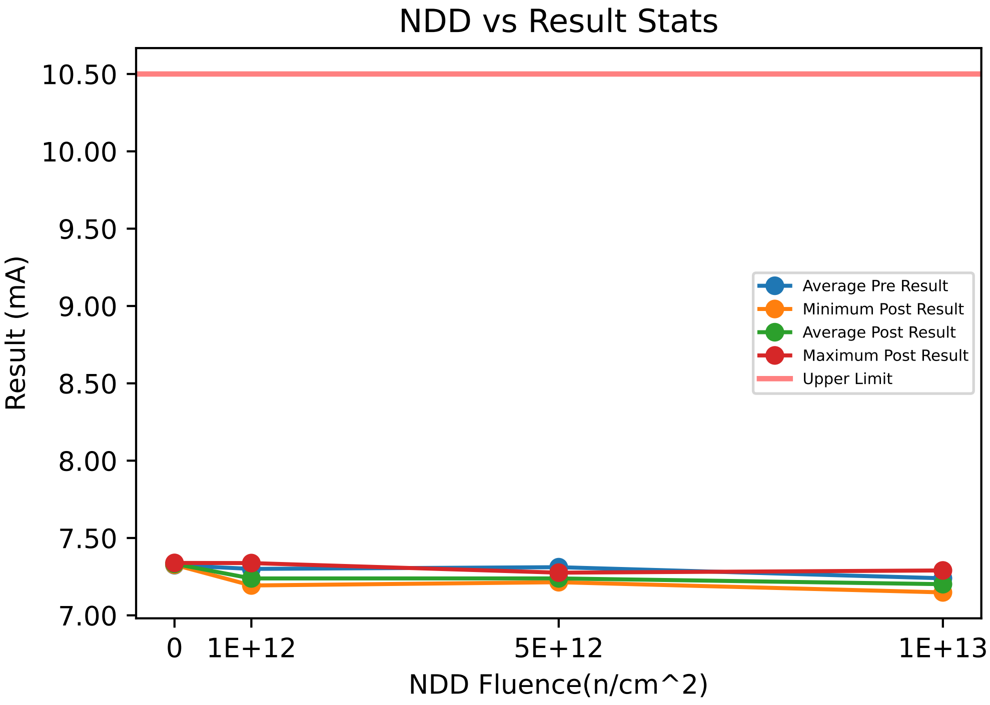
Test Results (Upper Limit = 17.0 (mA))

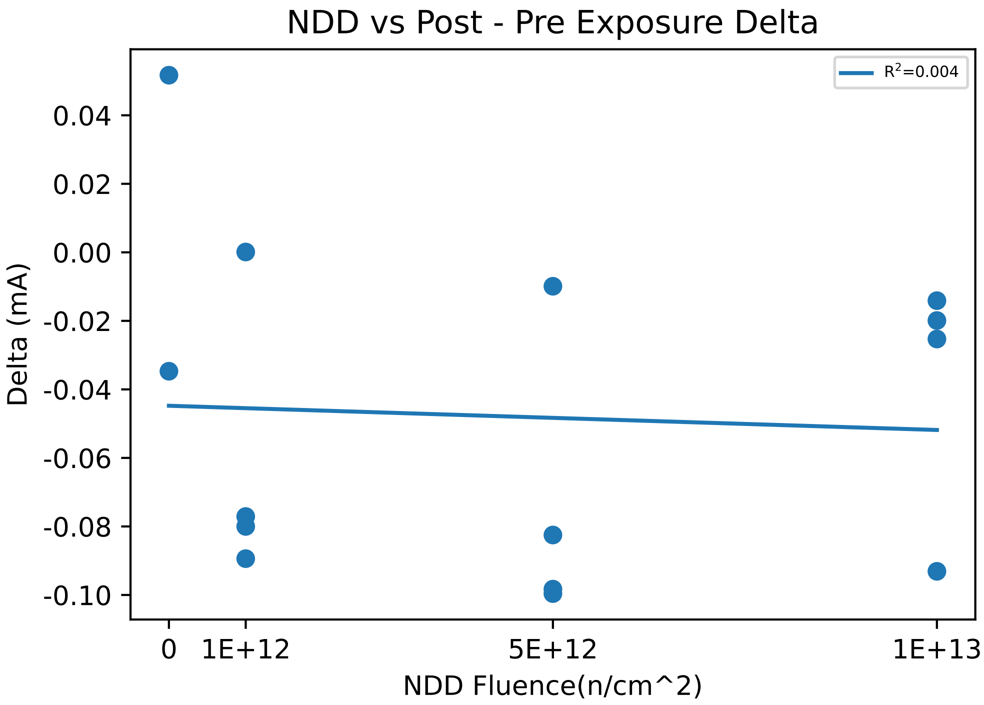
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	10.045	10.298	0.2536
2	0	Correlation	10.158	10.297	0.1394
30	1e+12	NDD unbiased	10.144	10.197	0.0527
31	1e+12	NDD unbiased	10.086	10.255	0.1689
32	1e+12	NDD unbiased	10.023	10.136	0.1132
33	1e+12	NDD unbiased	10.034	10.028	-0.0056
44	5e+12	NDD unbiased	9.924	10.037	0.1135
45	5e+12	NDD unbiased	10.065	10.184	0.1191
46	5e+12	NDD unbiased	10.039	10.153	0.1137
47	5e+12	NDD unbiased	10.087	10.187	0.1006
50	1e+13	NDD unbiased	10.228	10.188	-0.0405
51	1e+13	NDD unbiased	10.07	10.179	0.1085
52	1e+13	NDD unbiased	10.175	10.166	-0.0085
53	1e+13	NDD unbiased	10.22	10.191	-0.0287

Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	10.045	10.101	10.158	0.080186	10.297	10.298	10.298	0.00056569	0.1394	0.1965	0.2536	0.080752
1e+12	10.023	10.072	10.144	0.055604	10.028	10.154	10.255	0.097032	-0.0056	0.0823	0.1689	0.075403
5e+12	9.924	10.029	10.087	0.07251	10.037	10.14	10.187	0.070408	0.1006	0.11173	0.1191	0.0078572
1e+13	10.07	10.173	10.228	0.072644	10.166	10.181	10.191	0.011155	-0.0405	0.0077	0.1085	0.068487

Device Test: 37.19 I_OP_HS_IIM_2MHZ(_Iop HS BOOT IIM Interlock 2MHz VIN_14V)





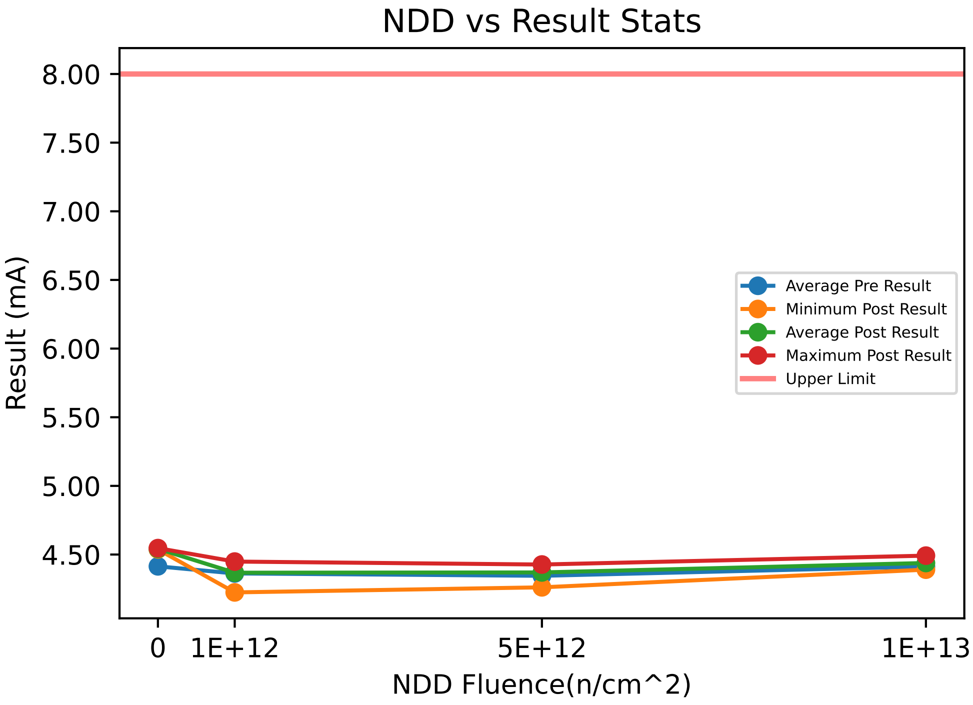
Test Results (Upper Limit = 10.5 (mA))

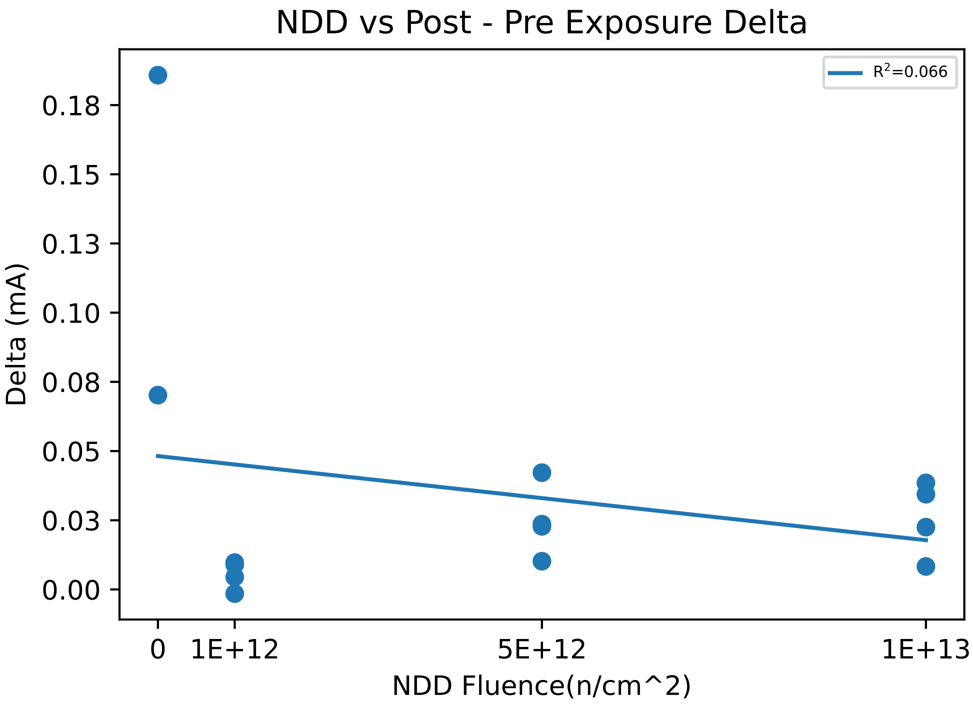
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	7.2748	7.3265	0.0517
2	0	Correlation	7.3736	7.3389	-0.0347
30	1e+12	NDD unbiased	7.2801	7.2001	-0.08
31	1e+12	NDD unbiased	7.2825	7.1931	-0.0894
32	1e+12	NDD unbiased	7.3005	7.2234	-0.0771
33	1e+12	NDD unbiased	7.3378	7.3379	0.0001
44	5e+12	NDD unbiased	7.3755	7.2759	-0.0996
45	5e+12	NDD unbiased	7.2409	7.231	-0.0099
46	5e+12	NDD unbiased	7.3124	7.2141	-0.0983
47	5e+12	NDD unbiased	7.3164	7.2339	-0.0825
50	1e+13	NDD unbiased	7.1736	7.1483	-0.0253
51	1e+13	NDD unbiased	7.2894	7.1963	-0.0931
52	1e+13	NDD unbiased	7.1851	7.171	-0.0141
53	1e+13	NDD unbiased	7.3101	7.2902	-0.0199

Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	7.2748	7.3242	7.3736	0.069862	7.3265	7.3327	7.3389	0.0087681	-0.0347	0.0085	0.0517	0.061094
1e+12	7.2801	7.3002	7.3378	0.026653	7.1931	7.2386	7.3379	0.067439	-0.0894	-0.0616	0.0001	0.041467
5e+12	7.2409	7.3113	7.3755	0.055091	7.2141	7.2387	7.2759	0.026276	-0.0996	-0.072575	-0.0099	0.0425
1e+13	7.1736	7.2396	7.3101	0.070182	7.1483	7.2014	7.2902	0.06233	-0.0931	-0.0381	-0.0141	0.036951

Device Test: 37.2 IQ_LS_IIM(_Iq LS VIN IIM Interlock VIN_14V)





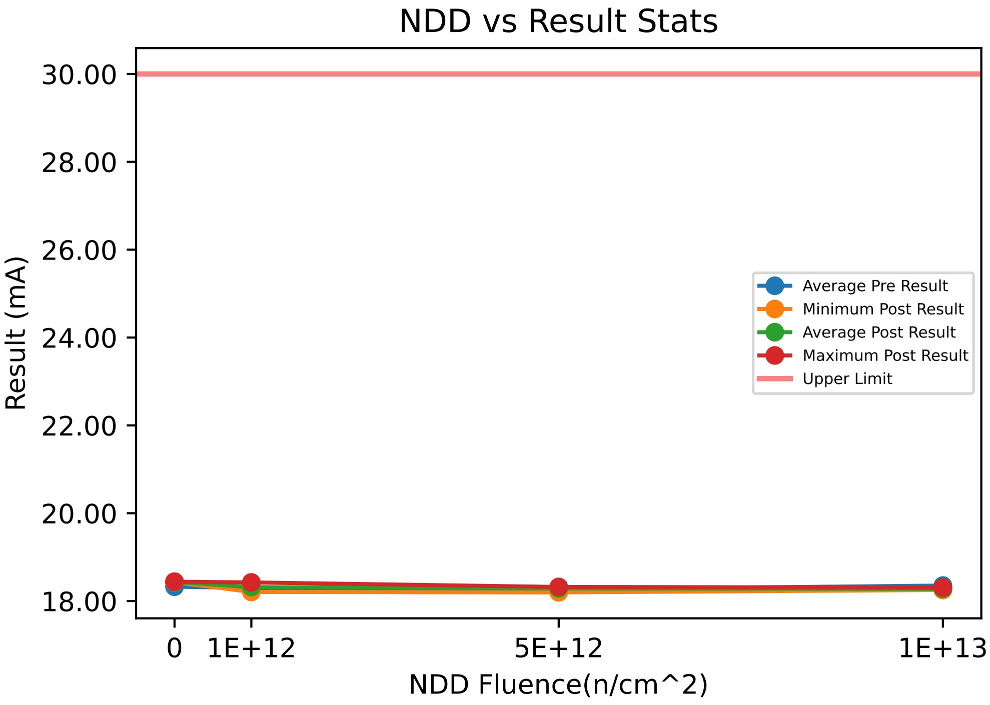
Test Results (Upper Limit = 8.0 (mA))

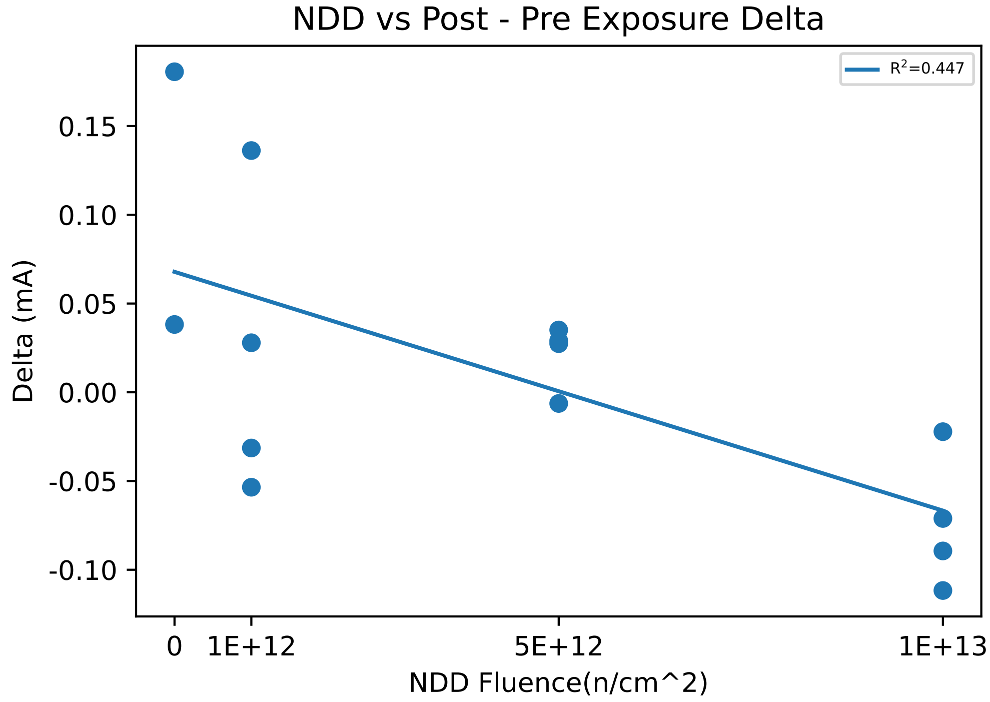
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	4.3609	4.5467	0.1858
2	0	Correlation	4.4672	4.5374	0.0702
30	1e+12	NDD unbiased	4.4397	4.4487	0.009
31	1e+12	NDD unbiased	4.4437	4.4422	-0.0015
32	1e+12	NDD unbiased	4.351	4.3555	0.0045
33	1e+12	NDD unbiased	4.2145	4.2242	0.0097
44	5e+12	NDD unbiased	4.2375	4.2611	0.0236
45	5e+12	NDD unbiased	4.3824	4.4246	0.0422
46	5e+12	NDD unbiased	4.3431	4.3659	0.0228
47	5e+12	NDD unbiased	4.4171	4.4273	0.0102
50	1e+13	NDD unbiased	4.4193	4.4276	0.0083
51	1e+13	NDD unbiased	4.4575	4.4919	0.0344
52	1e+13	NDD unbiased	4.3513	4.3898	0.0385
53	1e+13	NDD unbiased	4.4219	4.4444	0.0225

Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.3609	4.414	4.4672	0.075165	4.5374	4.542	4.5467	0.0065761	0.0702	0.128	0.1858	0.081742
1e+12	4.2145	4.3622	4.4437	0.10738	4.2242	4.3676	4.4487	0.10465	-0.0015	0.005425	0.0097	0.0051597
5e+12	4.2375	4.345	4.4171	0.077797	4.2611	4.3697	4.4273	0.077761	0.0102	0.0247	0.0422	0.013182
1e+13	4.3513	4.4125	4.4575	0.044366	4.3898	4.4384	4.4919	0.042335	0.0083	0.025925	0.0385	0.013569

Device Test: 37.20 I_OP_LS_IIM_5MHZ(_Iop LS VIN IIM Interlock 5MHz VIN_14V)





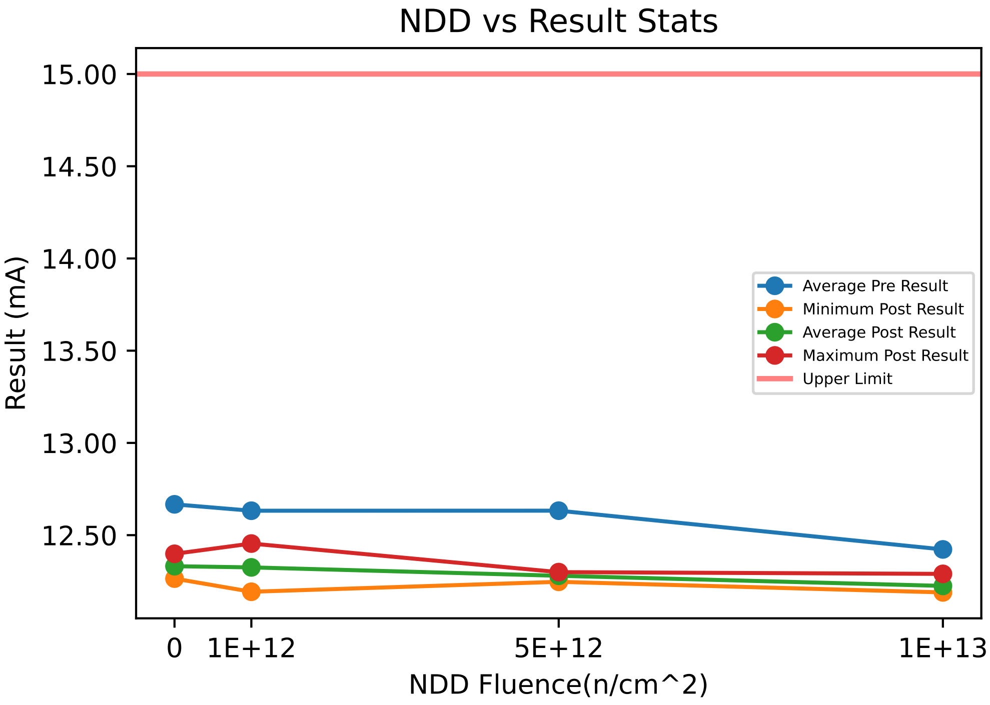
Test Results (Upper Limit = 30.0 (mA))

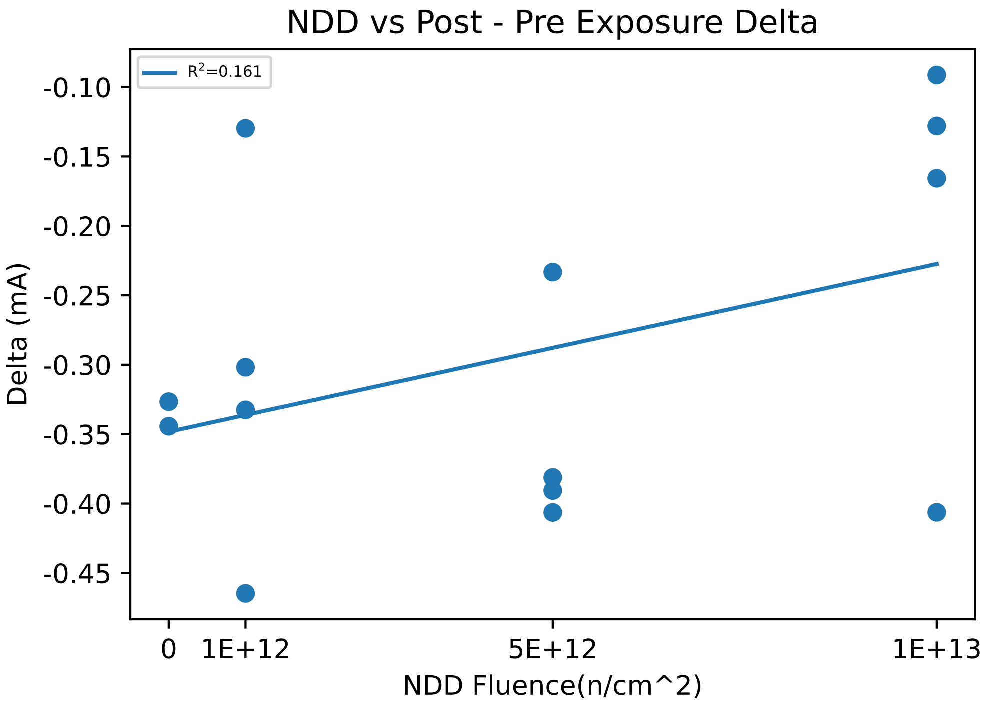
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	18.251	18.431	0.1806
2	0	Correlation	18.403	18.441	0.0382
30	1e+12	NDD unbiased	18.395	18.341	-0.0535
31	1e+12	NDD unbiased	18.288	18.424	0.1362
32	1e+12	NDD unbiased	18.268	18.296	0.0279
33	1e+12	NDD unbiased	18.238	18.207	-0.0314
44	5e+12	NDD unbiased	18.162	18.197	0.0351
45	5e+12	NDD unbiased	18.286	18.314	0.0274
46	5e+12	NDD unbiased	18.292	18.321	0.0291
47	5e+12	NDD unbiased	18.323	18.317	-0.0063
50	1e+13	NDD unbiased	18.4	18.288	-0.1117
51	1e+13	NDD unbiased	18.275	18.252	-0.0222
52	1e+13	NDD unbiased	18.377	18.306	-0.0711
53	1e+13	NDD unbiased	18.36	18.271	-0.0894

Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	18.251	18.327	18.403	0.10741	18.431	18.436	18.441	0.0067175	0.0382	0.1094	0.1806	0.10069
1e+12	18.238	18.297	18.395	0.068301	18.207	18.317	18.424	0.090643	-0.0535	0.0198	0.1362	0.08487
5e+12	18.162	18.266	18.323	0.070995	18.197	18.287	18.321	0.060044	-0.0063	0.021325	0.0351	0.01871
1e+13	18.275	18.353	18.4	0.054718	18.252	18.279	18.306	0.023058	-0.1117	-0.0736	-0.0222	0.038077

Device Test: 37.21 I_OP_HS_IIM_5MHZ(_Iop HS BOOT IIM Interlock 5MHz VIN_14V)


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

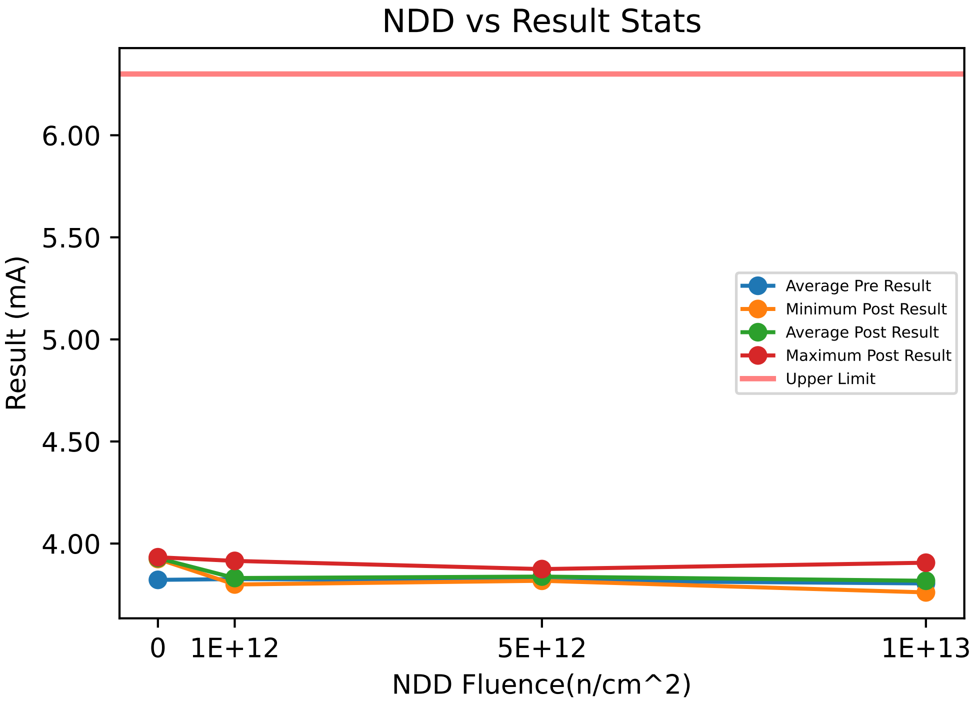
Test Results (Upper Limit = 15.0 (mA))

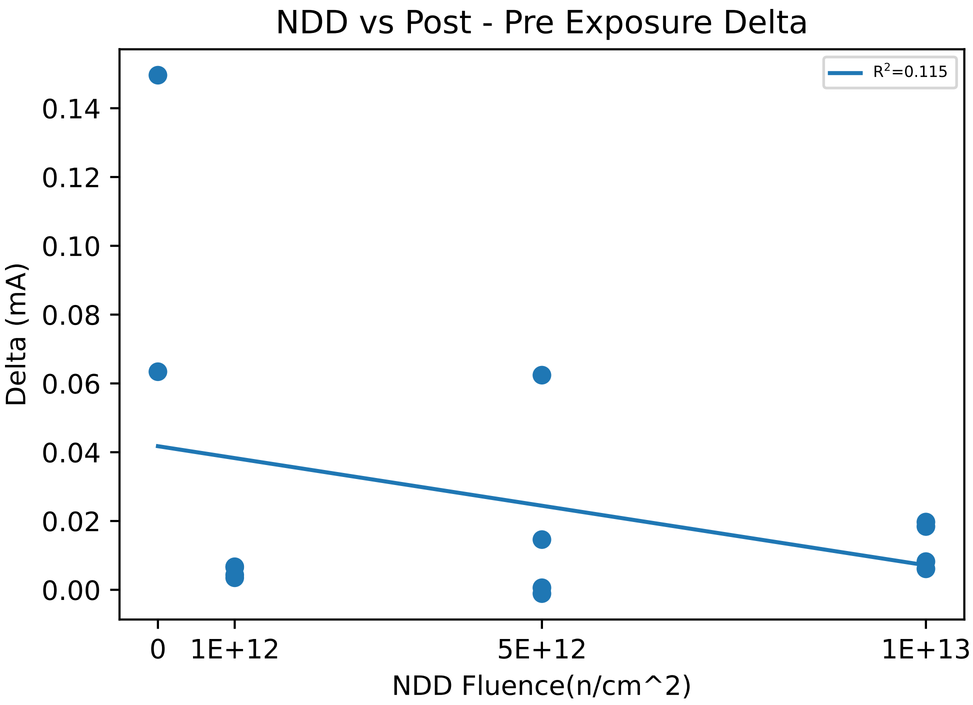
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	12.591	12.264	-0.3266
2	0	Correlation	12.743	12.399	-0.3443
30	1e+12	NDD unbiased	12.57	12.268	-0.3018
31	1e+12	NDD unbiased	12.658	12.193	-0.4647
32	1e+12	NDD unbiased	12.717	12.385	-0.3325
33	1e+12	NDD unbiased	12.584	12.454	-0.1297
44	5e+12	NDD unbiased	12.671	12.281	-0.3906
45	5e+12	NDD unbiased	12.525	12.292	-0.2333
46	5e+12	NDD unbiased	12.653	12.247	-0.4064
47	5e+12	NDD unbiased	12.681	12.3	-0.3812
50	1e+13	NDD unbiased	12.355	12.19	-0.1657
51	1e+13	NDD unbiased	12.6	12.193	-0.4063
52	1e+13	NDD unbiased	12.354	12.226	-0.128
53	1e+13	NDD unbiased	12.381	12.29	-0.0913

Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	12.591	12.667	12.743	0.10755	12.264	12.332	12.399	0.095035	-0.3443	-0.33545	-0.3266	0.012516
1e+12	12.57	12.632	12.717	0.068518	12.193	12.325	12.454	0.11683	-0.4647	-0.30717	-0.1297	0.13782
5e+12	12.525	12.633	12.681	0.072707	12.247	12.28	12.3	0.023126	-0.4064	-0.35287	-0.2333	0.080392
1e+13	12.354	12.423	12.6	0.11859	12.19	12.225	12.29	0.046515	-0.4063	-0.19783	-0.0913	0.14226

Device Test: 37.3 IQ_HS_IIM(_Iq HS BOOT IIM Interlock VIN_14V)





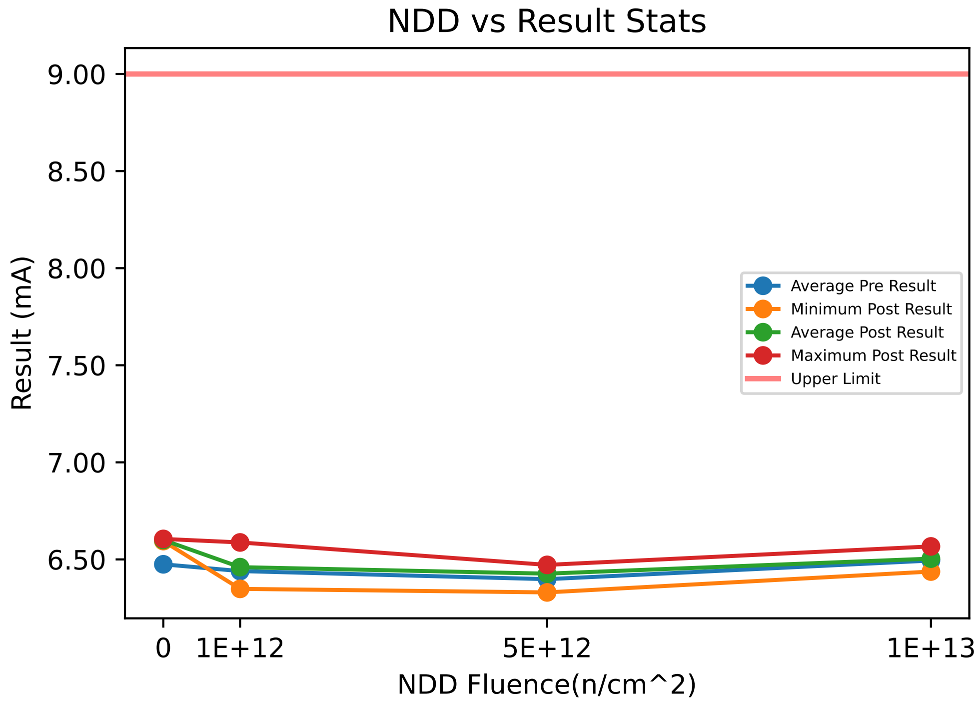
Test Results (Upper Limit = 6.3 (mA))

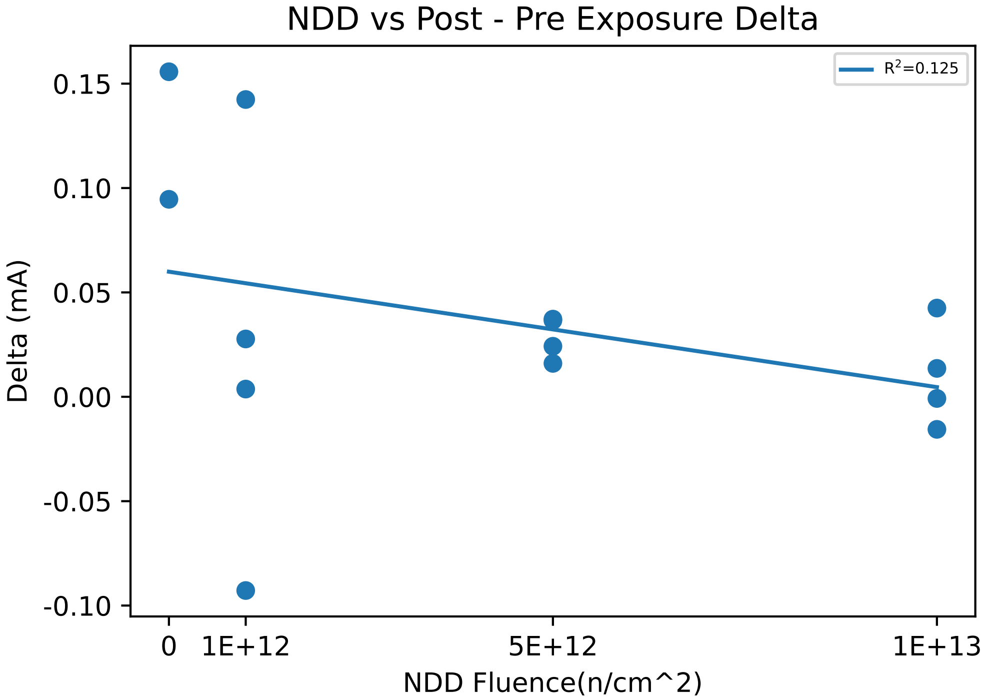
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	3.7833	3.9329	0.1496
2	0	Correlation	3.8609	3.9243	0.0634
30	1e+12	NDD unbiased	3.7985	3.8028	0.0043
31	1e+12	NDD unbiased	3.796	3.7995	0.0035
32	1e+12	NDD unbiased	3.8006	3.8073	0.0067
33	1e+12	NDD unbiased	3.9084	3.915	0.0066
44	5e+12	NDD unbiased	3.876	3.8749	-0.0011
45	5e+12	NDD unbiased	3.7667	3.8291	0.0624
46	5e+12	NDD unbiased	3.817	3.8176	0.0006
47	5e+12	NDD unbiased	3.8167	3.8313	0.0146
50	1e+13	NDD unbiased	3.7546	3.7607	0.0061
51	1e+13	NDD unbiased	3.8035	3.8232	0.0197
52	1e+13	NDD unbiased	3.7623	3.7807	0.0184
53	1e+13	NDD unbiased	3.8979	3.9061	0.0082

Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.7833	3.8221	3.8609	0.054871	3.9243	3.9286	3.9329	0.0060811	0.0634	0.1065	0.1496	0.060953
1e+12	3.796	3.8259	3.9084	0.055049	3.7995	3.8312	3.915	0.055991	0.0035	0.005275	0.0067	0.0016215
5e+12	3.7667	3.8191	3.876	0.044697	3.8176	3.8382	3.8749	0.025177	-0.0011	0.019125	0.0624	0.029695
1e+13	3.7546	3.8046	3.8979	0.065816	3.7607	3.8177	3.9061	0.064454	0.0061	0.0131	0.0197	0.0069441

Device Test: 37.6 I_OP_LS_PWM_500KHZ(_Iop LS VIN PWM 500kHz VIN_14V)





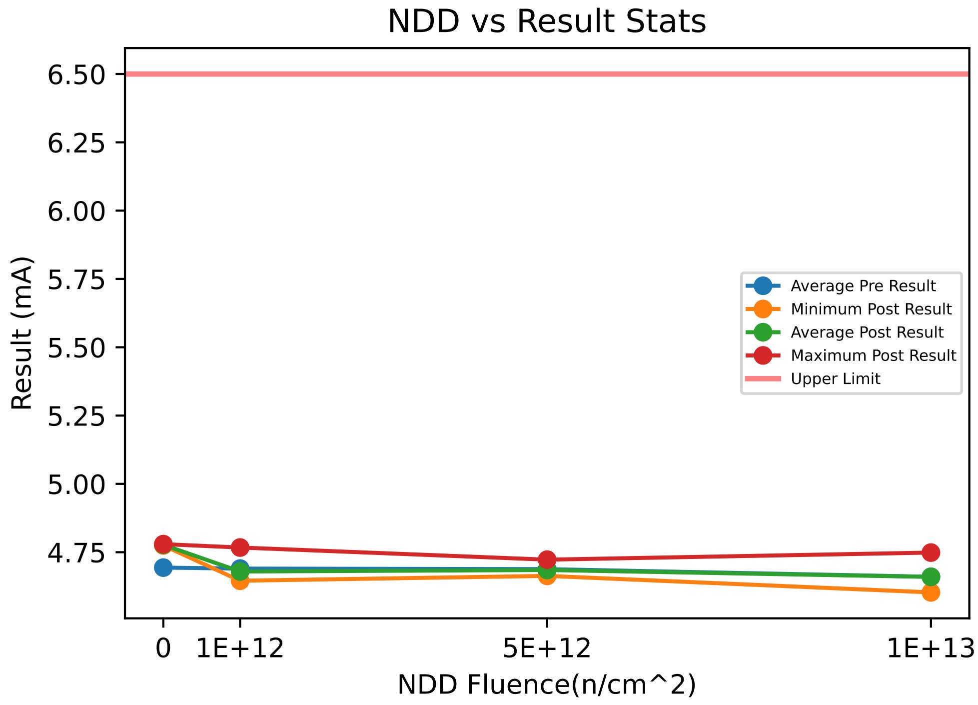
Test Results (Upper Limit = 9.0 (mA))

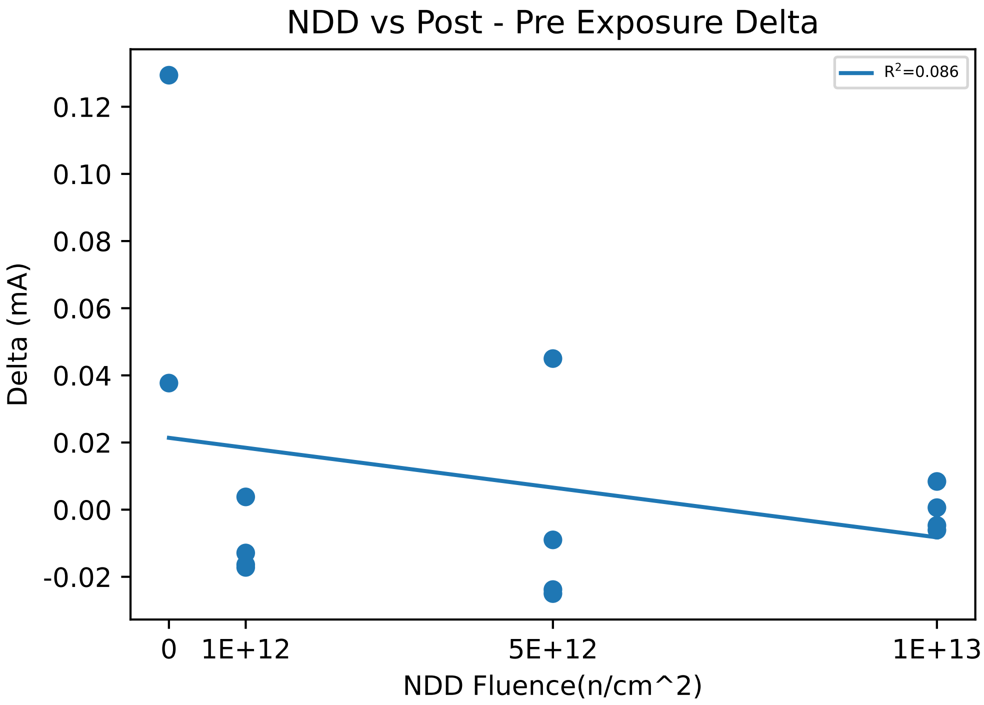
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	6.4386	6.5943	0.1557
2	0	Correlation	6.5109	6.6055	0.0946
30	1e+12	NDD unbiased	6.5619	6.4691	-0.0928
31	1e+12	NDD unbiased	6.445	6.5874	0.1424
32	1e+12	NDD unbiased	6.408	6.4357	0.0277
33	1e+12	NDD unbiased	6.3446	6.3483	0.0037
44	5e+12	NDD unbiased	6.2929	6.3301	0.0372
45	5e+12	NDD unbiased	6.455	6.471	0.016
46	5e+12	NDD unbiased	6.3972	6.4338	0.0366
47	5e+12	NDD unbiased	6.4476	6.4718	0.0242
50	1e+13	NDD unbiased	6.5597	6.5441	-0.0156
51	1e+13	NDD unbiased	6.395	6.4375	0.0425
52	1e+13	NDD unbiased	6.4541	6.4677	0.0136
53	1e+13	NDD unbiased	6.5677	6.5669	-0.0008

Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	6.4386	6.4748	6.5109	0.051124	6.5943	6.5999	6.6055	0.0079196	0.0946	0.12515	0.1557	0.043204
1e+12	6.3446	6.4399	6.5619	0.091305	6.3483	6.4601	6.5874	0.098963	-0.0928	0.02025	0.1424	0.096661
5e+12	6.2929	6.3982	6.455	0.074734	6.3301	6.4267	6.4718	0.066779	0.016	0.0285	0.0372	0.010264
1e+13	6.395	6.4941	6.5677	0.083947	6.4375	6.5041	6.5669	0.061385	-0.0156	0.009925	0.0425	0.024774

Device Test: 37.7 I_OP_HS_PWM_500KHZ(_Iop HS BOOT PWM 500kHz VIN_14V)





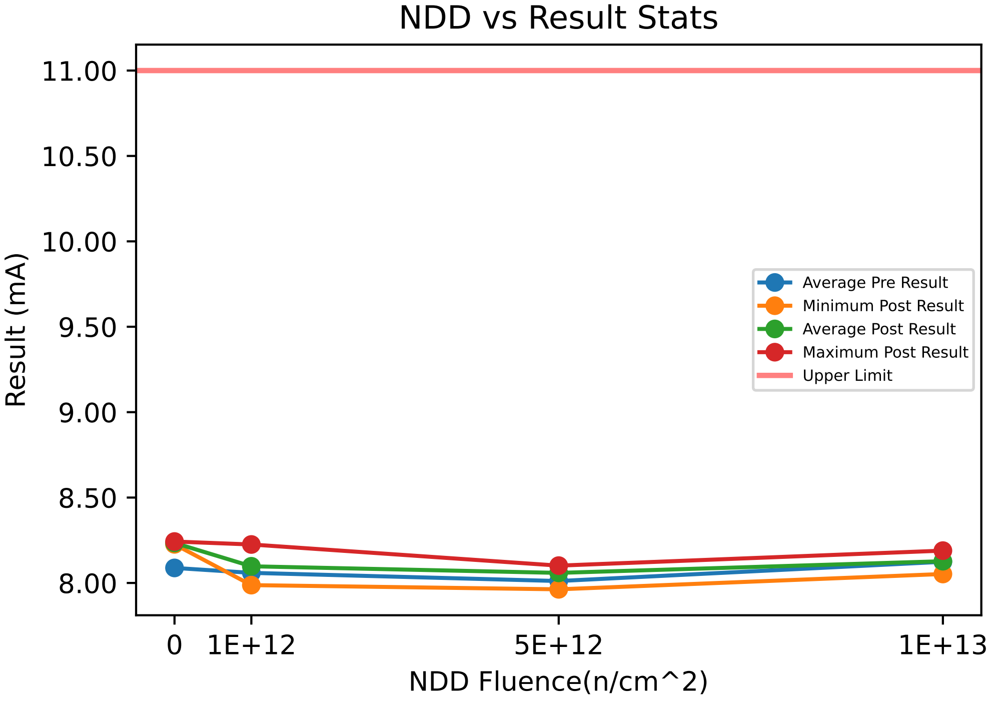
Test Results (Upper Limit = 6.5 (mA))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	4.6501	4.7795	0.1294
2	0	Correlation	4.737	4.7747	0.0377
30	1e+12	NDD unbiased	4.665	4.6478	-0.0172
31	1e+12	NDD unbiased	4.662	4.6456	-0.0164
32	1e+12	NDD unbiased	4.6699	4.657	-0.0129
33	1e+12	NDD unbiased	4.7633	4.7671	0.0038
44	5e+12	NDD unbiased	4.7477	4.7227	-0.025
45	5e+12	NDD unbiased	4.6311	4.6761	0.045
46	5e+12	NDD unbiased	4.6871	4.6633	-0.0238
47	5e+12	NDD unbiased	4.686	4.677	-0.009
50	1e+13	NDD unbiased	4.6076	4.6029	-0.0047
51	1e+13	NDD unbiased	4.6695	4.6634	-0.0061
52	1e+13	NDD unbiased	4.615	4.6234	0.0084
53	1e+13	NDD unbiased	4.748	4.7486	0.0006

Test Statistics (mA)

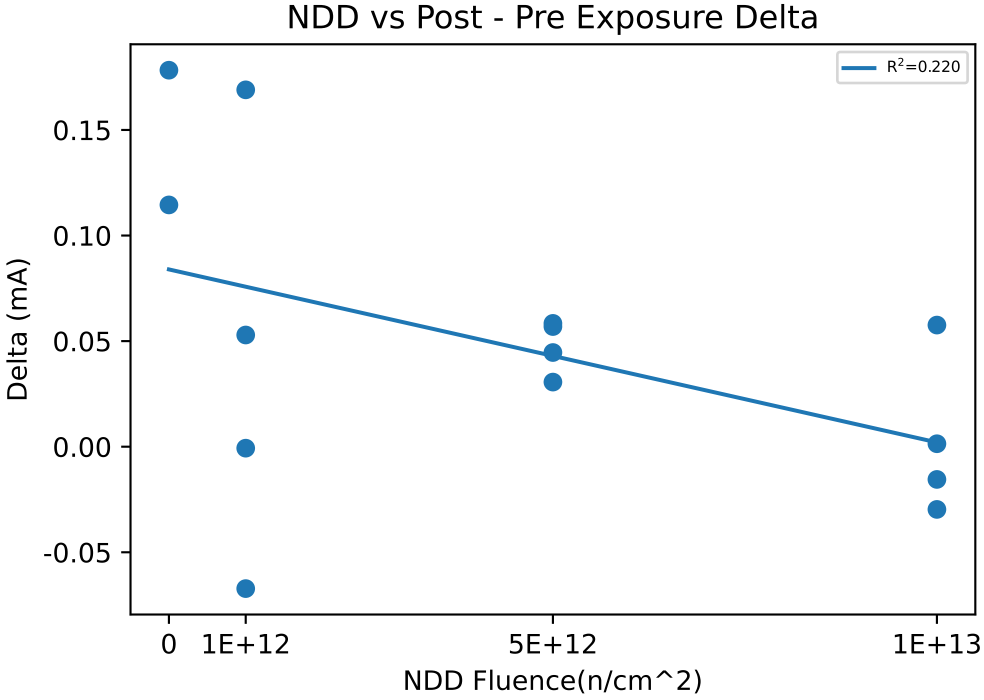
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.6501	4.6936	4.737	0.061448	4.7747	4.7771	4.7795	0.0033941	0.0377	0.08355	0.1294	0.064842
1e+12	4.662	4.6901	4.7633	0.048942	4.6456	4.6794	4.7671	0.058691	-0.0172	-0.010675	0.0038	0.009829
5e+12	4.6311	4.688	4.7477	0.047632	4.6633	4.6848	4.7227	0.026046	-0.025	-0.0032	0.045	0.032947
1e+13	4.6076	4.66	4.748	0.06482	4.6029	4.6596	4.7486	0.064448	-0.0061	-0.00045	0.0084	0.0065679

Device Test: 37.8 I_OP_LS_PWM_1MHZ(_Iop LS VIN PWM 1MHz VIN_14V)



Test Results (Upper Limit = 11.0 (mA))

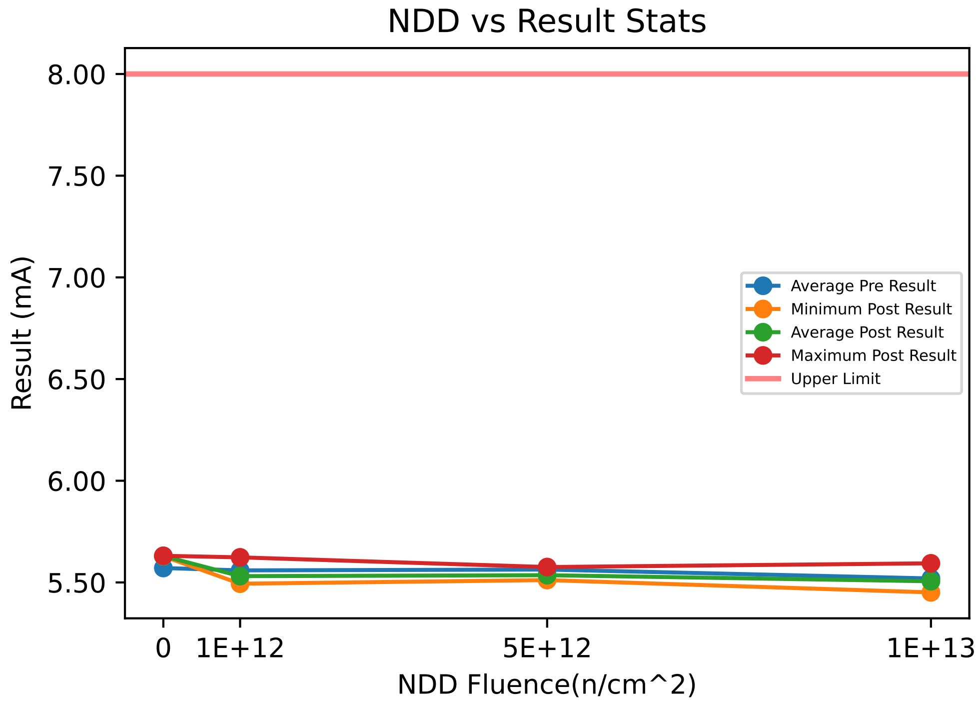
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	8.0479	8.2262	0.1783
2	0	Correlation	8.1281	8.2426	0.1145
30	1e+12	NDD unbiased	8.1741	8.1069	-0.0672
31	1e+12	NDD unbiased	8.0563	8.2253	0.169
32	1e+12	NDD unbiased	8.0181	8.071	0.0529
33	1e+12	NDD unbiased	7.9881	7.9874	-0.0007
44	5e+12	NDD unbiased	7.9059	7.9628	0.0569
45	5e+12	NDD unbiased	8.069	8.0996	0.0306
46	5e+12	NDD unbiased	8.0136	8.072	0.0584
47	5e+12	NDD unbiased	8.0569	8.1015	0.0446
50	1e+13	NDD unbiased	8.1981	8.1684	-0.0297
51	1e+13	NDD unbiased	7.9949	8.0525	0.0576
52	1e+13	NDD unbiased	8.0979	8.0993	0.0014
53	1e+13	NDD unbiased	8.2048	8.1893	-0.0155

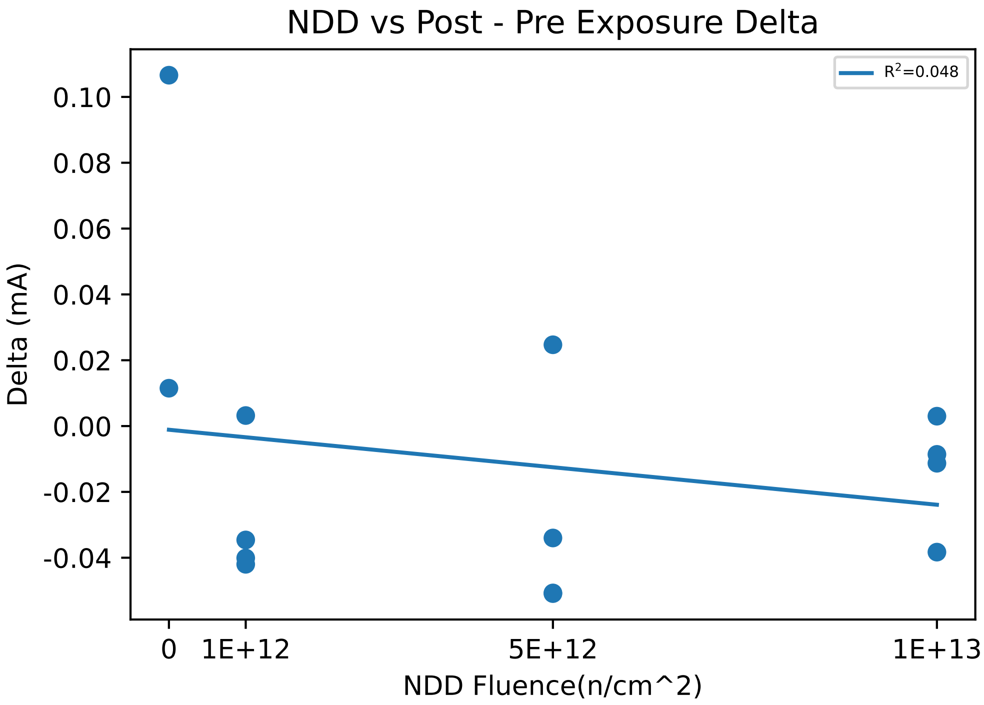


Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	8.0479	8.088	8.1281	0.05671	8.2262	8.2344	8.2426	0.011597	0.1145	0.1464	0.1783	0.045113
1e+12	7.9881	8.0592	8.1741	0.081557	7.9874	8.0976	8.2253	0.098734	-0.0672	0.0385	0.169	0.099911
5e+12	7.9059	8.0114	8.069	0.074214	7.9628	8.059	8.1015	0.065519	0.0306	0.047625	0.0584	0.012924
1e+13	7.9949	8.1239	8.2048	0.09894	8.0525	8.1274	8.1893	0.063014	-0.0297	0.00345	0.0576	0.038273

Device Test: 37.9 I_OP_HS_PWM_1MHZ(_Iop HS BOOT PWM 1MHz VIN_14V)


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

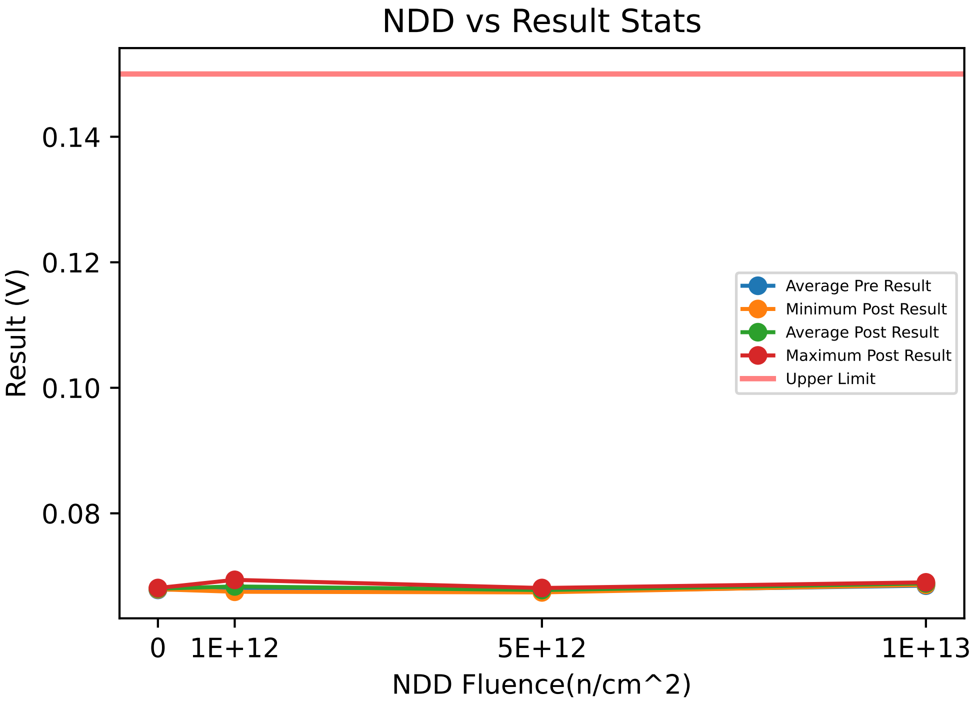
Test Results (Upper Limit = 8.0 (mA))

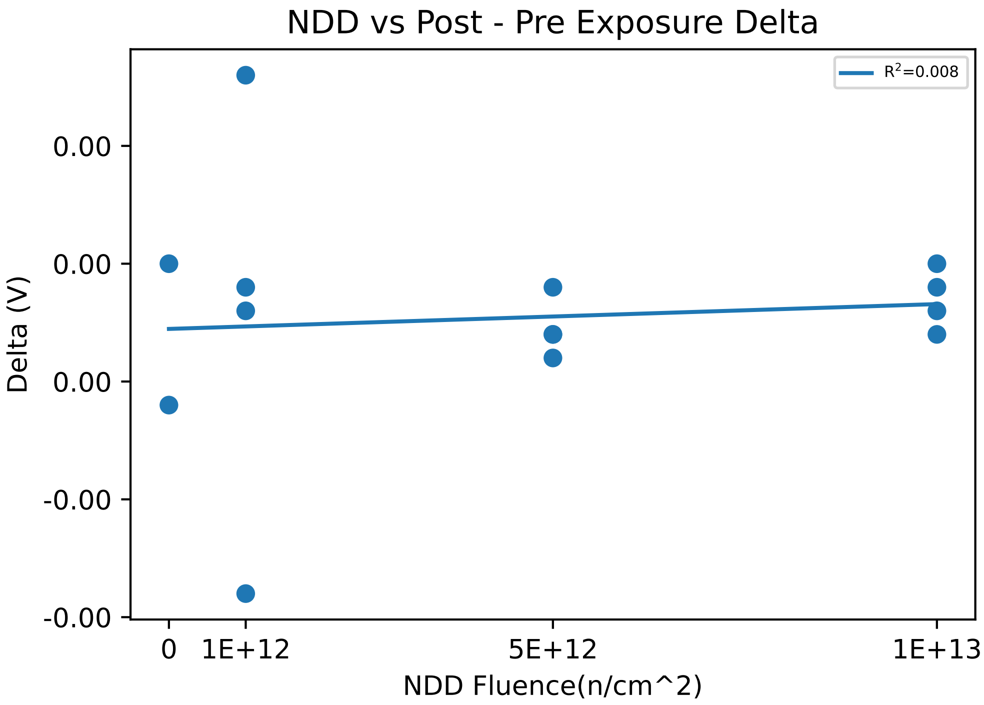
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	5.5244	5.631	0.1066
2	0	Correlation	5.6174	5.6289	0.0115
30	1e+12	NDD unbiased	5.5375	5.4974	-0.0401
31	1e+12	NDD unbiased	5.5357	5.4937	-0.042
32	1e+12	NDD unbiased	5.5436	5.509	-0.0346
33	1e+12	NDD unbiased	5.6201	5.6233	0.0032
44	5e+12	NDD unbiased	5.6266	5.5757	-0.0509
45	5e+12	NDD unbiased	5.5022	5.5269	0.0247
46	5e+12	NDD unbiased	5.5622	5.5115	-0.0507
47	5e+12	NDD unbiased	5.5622	5.5282	-0.034
50	1e+13	NDD unbiased	5.4623	5.451	-0.0113
51	1e+13	NDD unbiased	5.5429	5.5046	-0.0383
52	1e+13	NDD unbiased	5.4704	5.4734	0.003
53	1e+13	NDD unbiased	5.6026	5.594	-0.0086

Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.5244	5.5709	5.6174	0.065761	5.6289	5.63	5.631	0.0014849	0.0115	0.05905	0.1066	0.067246
1e+12	5.5357	5.5592	5.6201	0.040724	5.4937	5.5309	5.6233	0.061977	-0.042	-0.028375	0.0032	0.021283
5e+12	5.5022	5.5633	5.6266	0.050802	5.5115	5.5356	5.5757	0.027804	-0.0509	-0.027725	0.0247	0.035836
1e+13	5.4623	5.5195	5.6026	0.066171	5.451	5.5057	5.594	0.062805	-0.0383	-0.0138	0.003	0.017472

Device Test: 45.0 V_OL(_VOL LO VIN_10V)





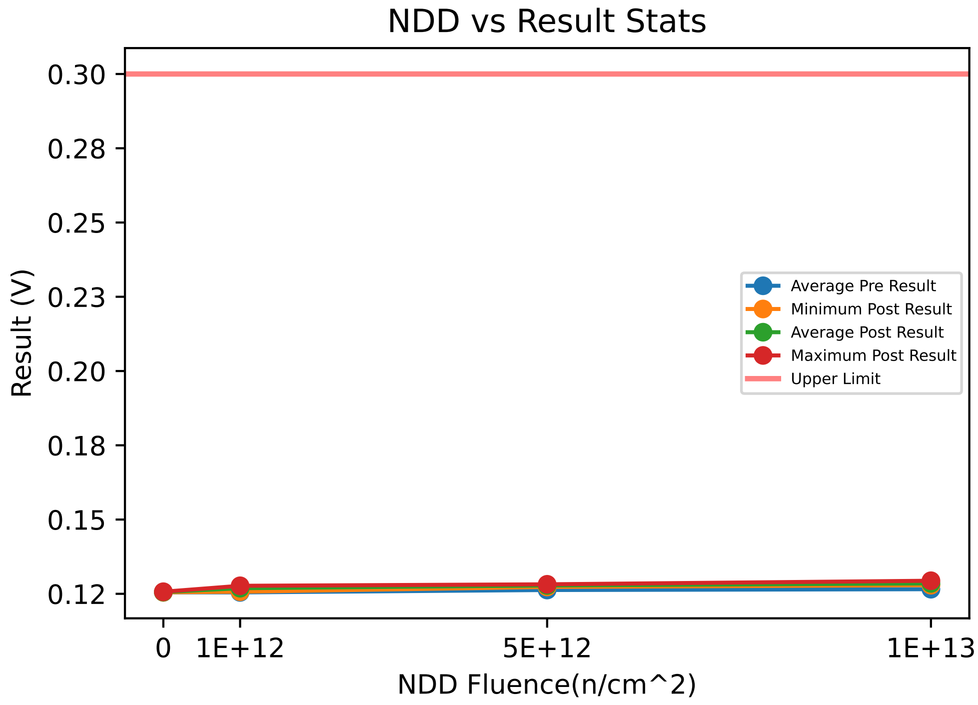
Test Results (Upper Limit = 0.15 (V))

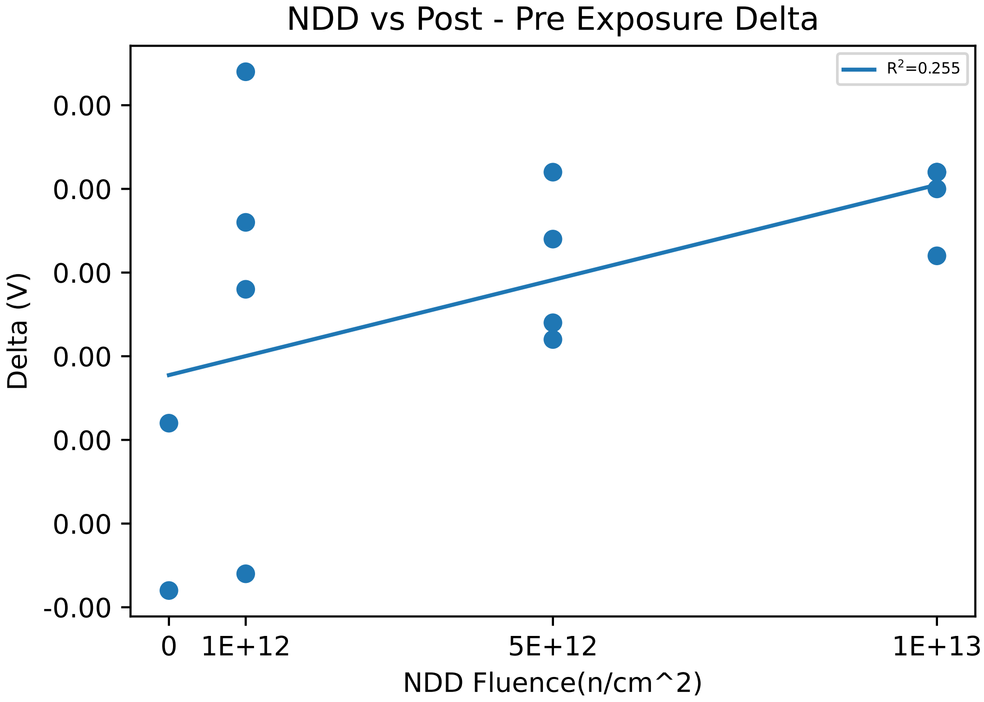
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	0.0674	0.0679	0.0005
2	0	Correlation	0.0682	0.0681	-0.0001
30	1e+12	NDD unbiased	0.0675	0.0688	0.0013
31	1e+12	NDD unbiased	0.0686	0.0677	-0.0009
32	1e+12	NDD unbiased	0.0691	0.0694	0.0003
33	1e+12	NDD unbiased	0.0671	0.0675	0.0004
44	5e+12	NDD unbiased	0.0672	0.0676	0.0004
45	5e+12	NDD unbiased	0.0678	0.068	0.0002
46	5e+12	NDD unbiased	0.0673	0.0674	0.0001
47	5e+12	NDD unbiased	0.0679	0.0681	0.0002
50	1e+13	NDD unbiased	0.0687	0.069	0.0003
51	1e+13	NDD unbiased	0.0687	0.0689	0.0002
52	1e+13	NDD unbiased	0.0682	0.0686	0.0004
53	1e+13	NDD unbiased	0.0683	0.0688	0.0005

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.0674	0.0678	0.0682	0.00056569	0.0679	0.068	0.0681	0.00014142	-0.0001	0.0002	0.0005	0.00042426
1e+12	0.0671	0.068075	0.0691	0.00093229	0.0675	0.06835	0.0694	0.0009037	-0.0009	0.000275	0.0013	0.00090323
5e+12	0.0672	0.06755	0.0679	0.00035119	0.0674	0.067775	0.0681	0.0003304	0.0001	0.000225	0.0004	0.00012583
1e+13	0.0682	0.068475	0.0687	0.000263	0.0686	0.068825	0.069	0.00017078	0.0002	0.00035	0.0005	0.0001291

Device Test: 45.2 V_OH_DELTA(_VOH Delta LO VIN_10V)


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

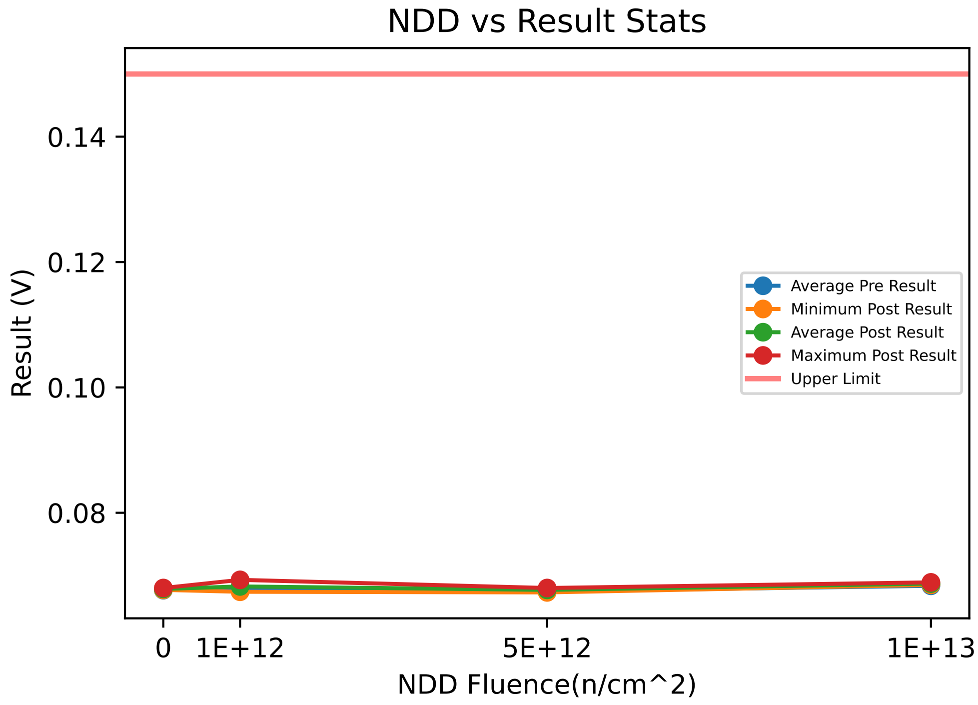
Test Results (Upper Limit = 0.3 (V))

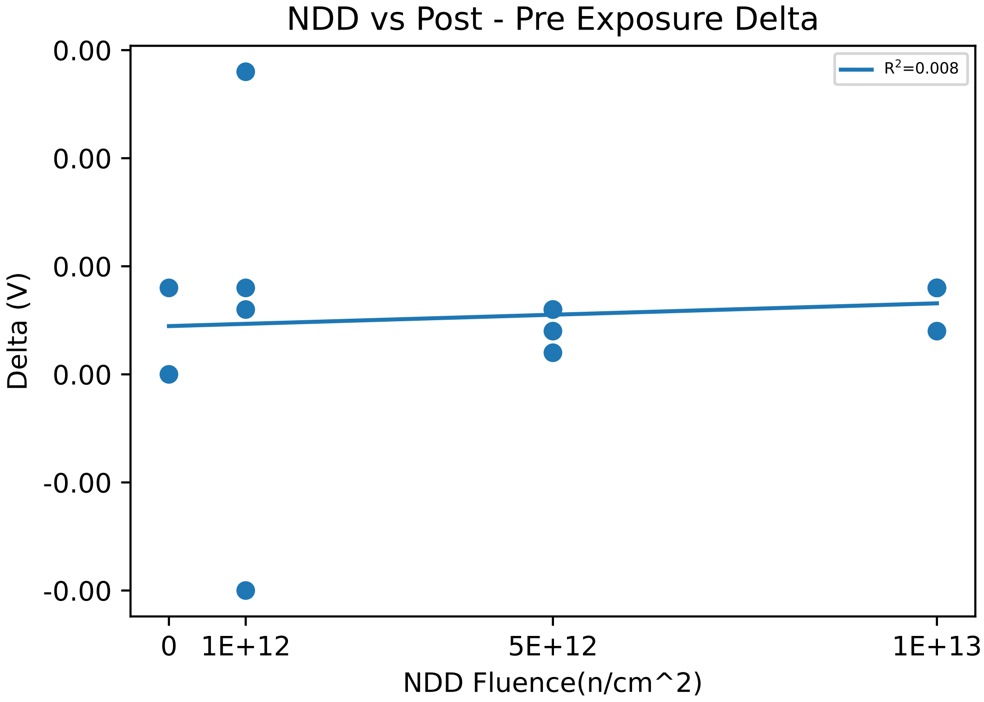
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	0.1249	0.1255	0.0006
2	0	Correlation	0.1261	0.1257	-0.0004
30	1e+12	NDD unbiased	0.125	0.1277	0.0027
31	1e+12	NDD unbiased	0.126	0.1257	-0.0003
32	1e+12	NDD unbiased	0.1258	0.1272	0.0014
33	1e+12	NDD unbiased	0.1251	0.1269	0.0018
44	5e+12	NDD unbiased	0.1265	0.1277	0.0012
45	5e+12	NDD unbiased	0.1259	0.128	0.0021
46	5e+12	NDD unbiased	0.1256	0.1273	0.0017
47	5e+12	NDD unbiased	0.1271	0.1282	0.0011
50	1e+13	NDD unbiased	0.1273	0.1294	0.0021
51	1e+13	NDD unbiased	0.1265	0.1281	0.0016
52	1e+13	NDD unbiased	0.1265	0.1286	0.0021
53	1e+13	NDD unbiased	0.1259	0.1279	0.002

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.1249	0.1255	0.1261	0.00084853	0.1255	0.1256	0.1257	0.00014142	-0.0004	0.0001	0.0006	0.00070711
1e+12	0.125	0.12548	0.126	0.00049917	0.1257	0.12688	0.1277	0.00085	-0.0003	0.0014	0.0027	0.001257
5e+12	0.1256	0.12627	0.1271	0.00066521	0.1273	0.1278	0.1282	0.00039158	0.0011	0.001525	0.0021	0.00046458
1e+13	0.1259	0.12655	0.1273	0.00057446	0.1279	0.1285	0.1294	0.00066833	0.0016	0.00195	0.0021	0.00023805

Device Test: 46.0 V_OL(_VOL LO VIN_12V)





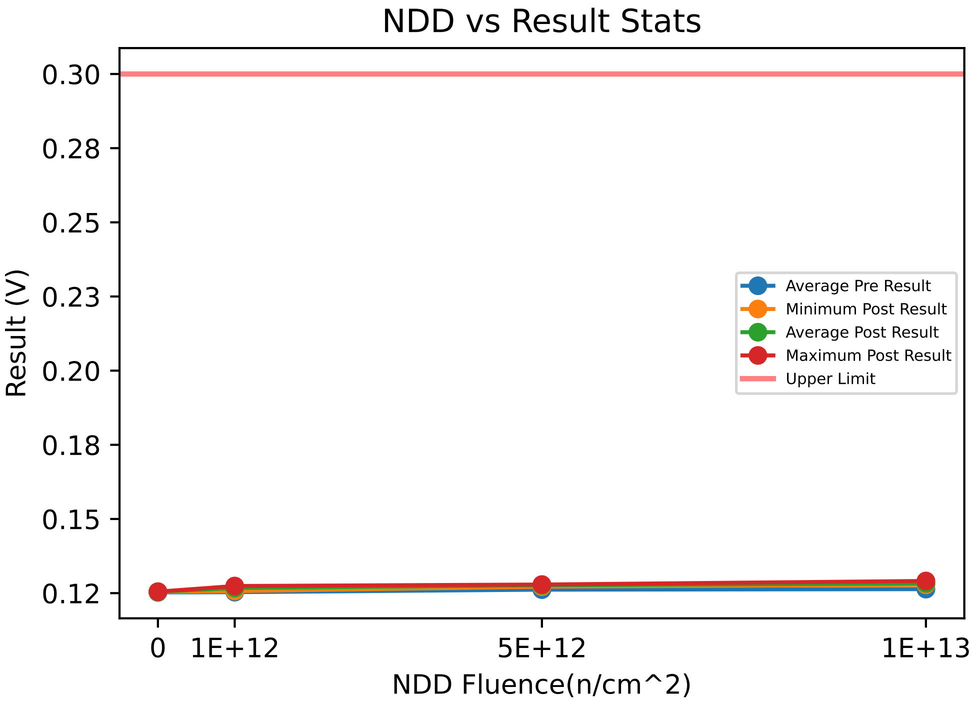
Test Results (Upper Limit = 0.15 (V))

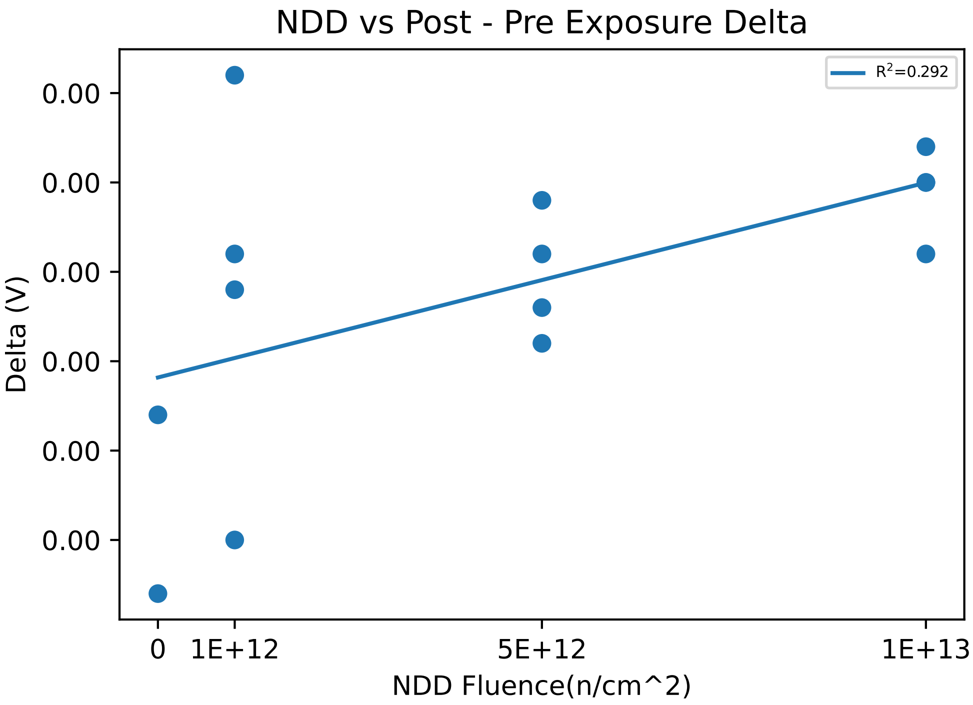
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	0.0673	0.0677	0.0004
2	0	Correlation	0.068	0.068	0
30	1e+12	NDD unbiased	0.0674	0.0688	0.0014
31	1e+12	NDD unbiased	0.0685	0.0675	-0.001
32	1e+12	NDD unbiased	0.069	0.0693	0.0003
33	1e+12	NDD unbiased	0.067	0.0674	0.0004
44	5e+12	NDD unbiased	0.0672	0.0675	0.0003
45	5e+12	NDD unbiased	0.0677	0.068	0.0003
46	5e+12	NDD unbiased	0.0672	0.0673	0.0001
47	5e+12	NDD unbiased	0.0678	0.068	0.0002
50	1e+13	NDD unbiased	0.0685	0.0689	0.0004
51	1e+13	NDD unbiased	0.0686	0.0688	0.0002
52	1e+13	NDD unbiased	0.0681	0.0685	0.0004
53	1e+13	NDD unbiased	0.0682	0.0686	0.0004

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.0673	0.06765	0.068	0.00049497	0.0677	0.06785	0.068	0.00021213	0	0.0002	0.0004	0.00028284
1e+12	0.067	0.067975	0.069	0.00093229	0.0674	0.06825	0.0693	0.00094692	-0.001	0.000275	0.0014	0.00098446
5e+12	0.0672	0.067475	0.0678	0.00032016	0.0673	0.0677	0.068	0.0003559	0.0001	0.000225	0.0003	9.5743e-05
1e+13	0.0681	0.06835	0.0686	0.00023805	0.0685	0.0687	0.0689	0.00018257	0.0002	0.00035	0.0004	0.0001

Device Test: 46.2 V_OH_DELTA(_VOH Delta LO VIN_12V)


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

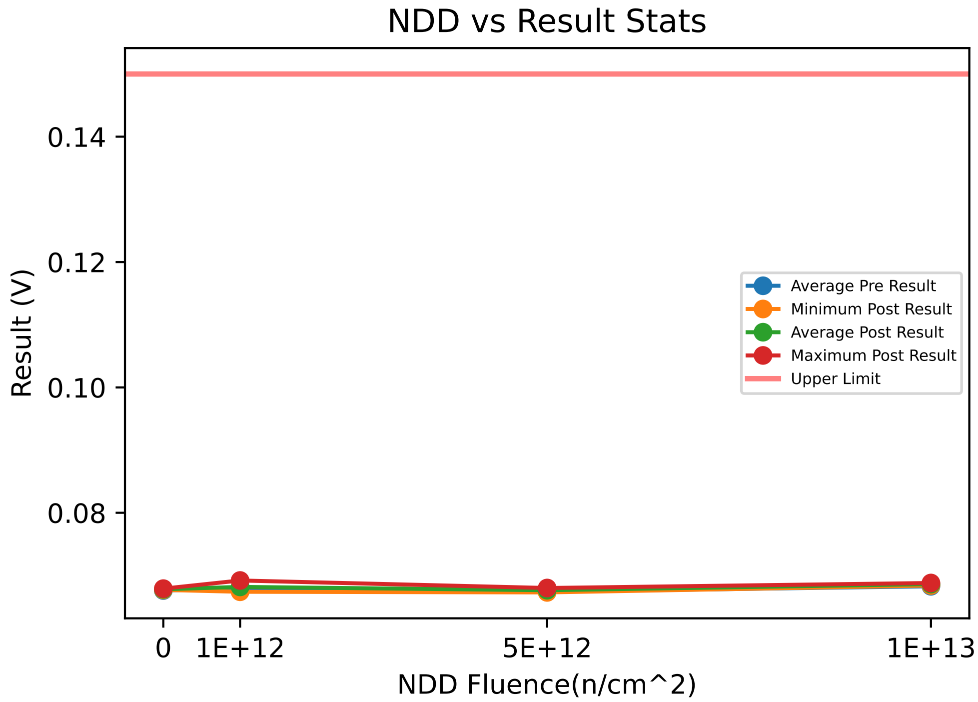
Test Results (Upper Limit = 0.3 (V))

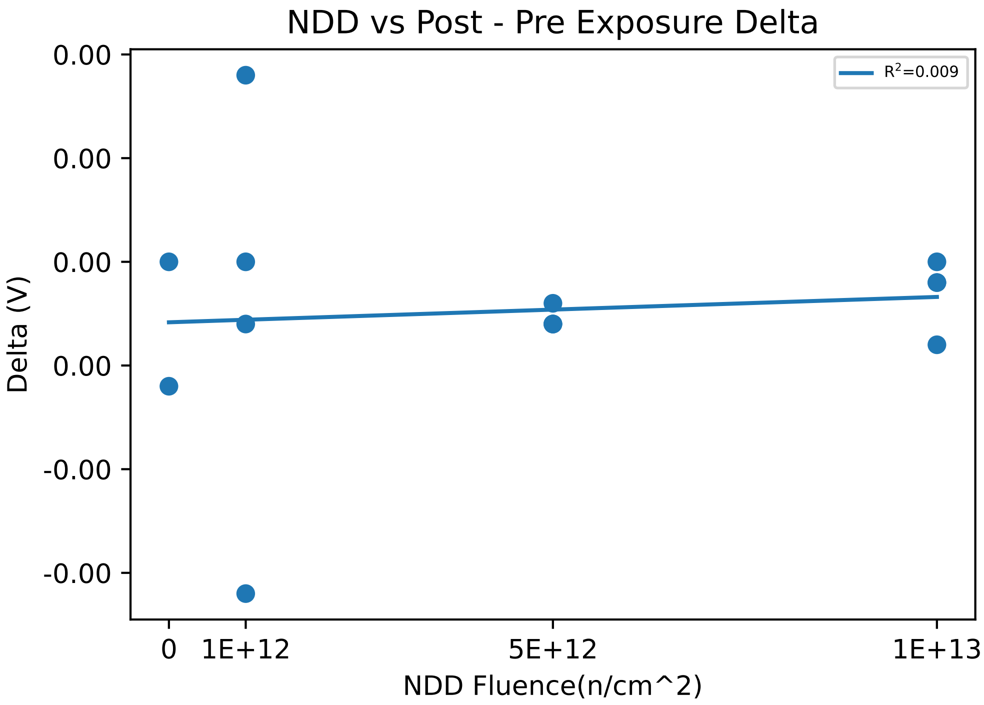
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	0.1247	0.1254	0.0007
2	0	Correlation	0.1258	0.1255	-0.0003
30	1e+12	NDD unbiased	0.1248	0.1274	0.0026
31	1e+12	NDD unbiased	0.1257	0.1257	0
32	1e+12	NDD unbiased	0.1258	0.1272	0.0014
33	1e+12	NDD unbiased	0.125	0.1266	0.0016
44	5e+12	NDD unbiased	0.1264	0.1277	0.0013
45	5e+12	NDD unbiased	0.1259	0.1278	0.0019
46	5e+12	NDD unbiased	0.1256	0.1272	0.0016
47	5e+12	NDD unbiased	0.1268	0.1279	0.0011
50	1e+13	NDD unbiased	0.1271	0.1291	0.002
51	1e+13	NDD unbiased	0.1263	0.1279	0.0016
52	1e+13	NDD unbiased	0.1262	0.1284	0.0022
53	1e+13	NDD unbiased	0.1258	0.1278	0.002

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.1247	0.12525	0.1258	0.00077782	0.1254	0.12545	0.1255	7.0711e-05	-0.0003	0.0002	0.0007	0.00070711
1e+12	0.1248	0.12532	0.1258	0.00049917	0.1257	0.12673	0.1274	0.00076322	0	0.0014	0.0026	0.0010708
5e+12	0.1256	0.12618	0.1268	0.00053151	0.1272	0.12765	0.1279	0.00031091	0.0011	0.001475	0.0019	0.00035
1e+13	0.1258	0.12635	0.1271	0.00054467	0.1278	0.1283	0.1291	0.00059442	0.0016	0.00195	0.0022	0.00025166

Device Test: 47.0 V_OL(_VOL LO VIN_14V)


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

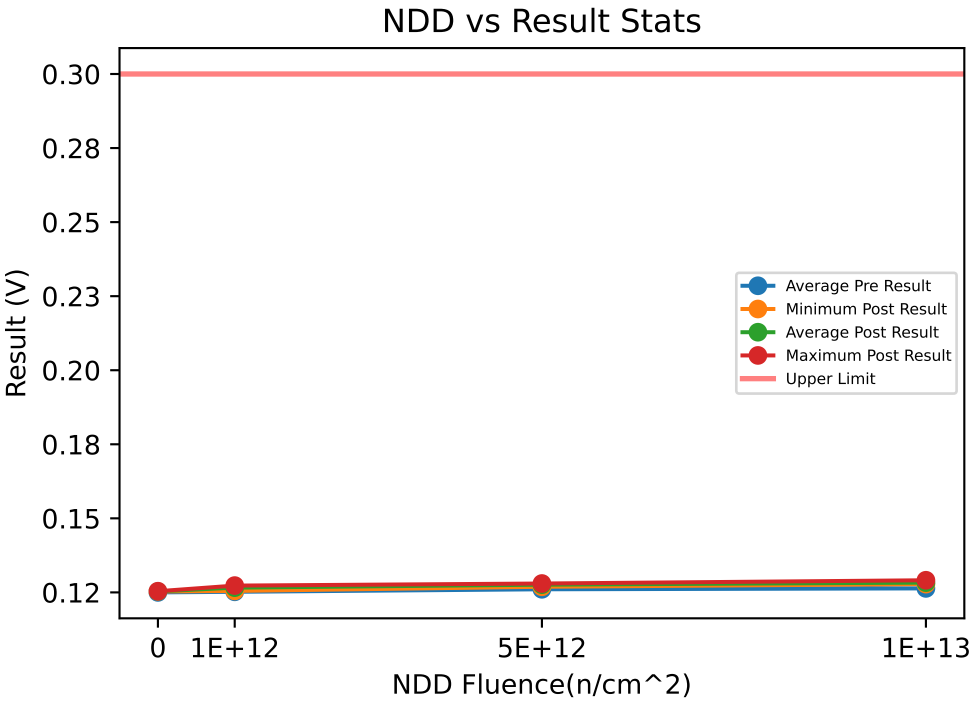
Test Results (Upper Limit = 0.15 (V))

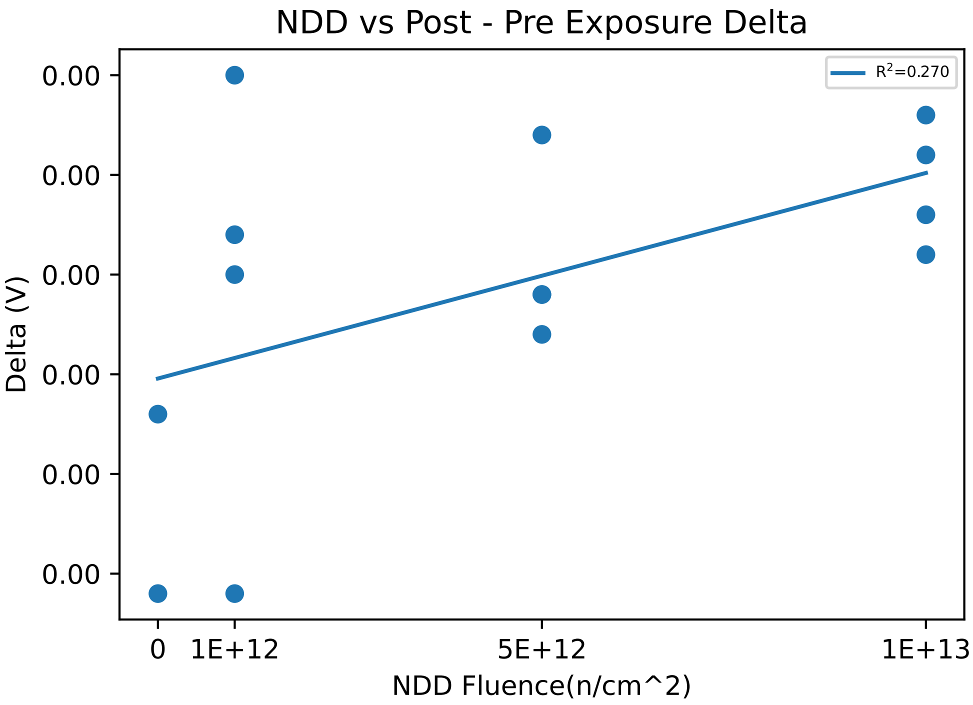
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	0.0672	0.0677	0.0005
2	0	Correlation	0.068	0.0679	-0.0001
30	1e+12	NDD unbiased	0.0673	0.0687	0.0014
31	1e+12	NDD unbiased	0.0685	0.0674	-0.0011
32	1e+12	NDD unbiased	0.069	0.0692	0.0002
33	1e+12	NDD unbiased	0.0669	0.0674	0.0005
44	5e+12	NDD unbiased	0.0671	0.0674	0.0003
45	5e+12	NDD unbiased	0.0677	0.0679	0.0002
46	5e+12	NDD unbiased	0.0671	0.0673	0.0002
47	5e+12	NDD unbiased	0.0678	0.068	0.0002
50	1e+13	NDD unbiased	0.0684	0.0688	0.0004
51	1e+13	NDD unbiased	0.0686	0.0687	0.0001
52	1e+13	NDD unbiased	0.068	0.0684	0.0004
53	1e+13	NDD unbiased	0.0681	0.0686	0.0005

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.0672	0.0676	0.068	0.00056569	0.0677	0.0678	0.0679	0.00014142	-0.0001	0.0002	0.0005	0.00042426
1e+12	0.0669	0.067925	0.069	0.00098784	0.0674	0.068175	0.0692	0.00091788	-0.0011	0.00025	0.0014	0.0010344
5e+12	0.0671	0.067425	0.0678	0.00037749	0.0673	0.06765	0.068	0.00035119	0.0002	0.000225	0.0003	5e-05
1e+13	0.068	0.068275	0.0686	0.00027538	0.0684	0.068625	0.0688	0.00017078	0.0001	0.00035	0.0005	0.00017321

Device Test: 47.2 V_OH_DELTA(_VOH Delta LO VIN_14V)





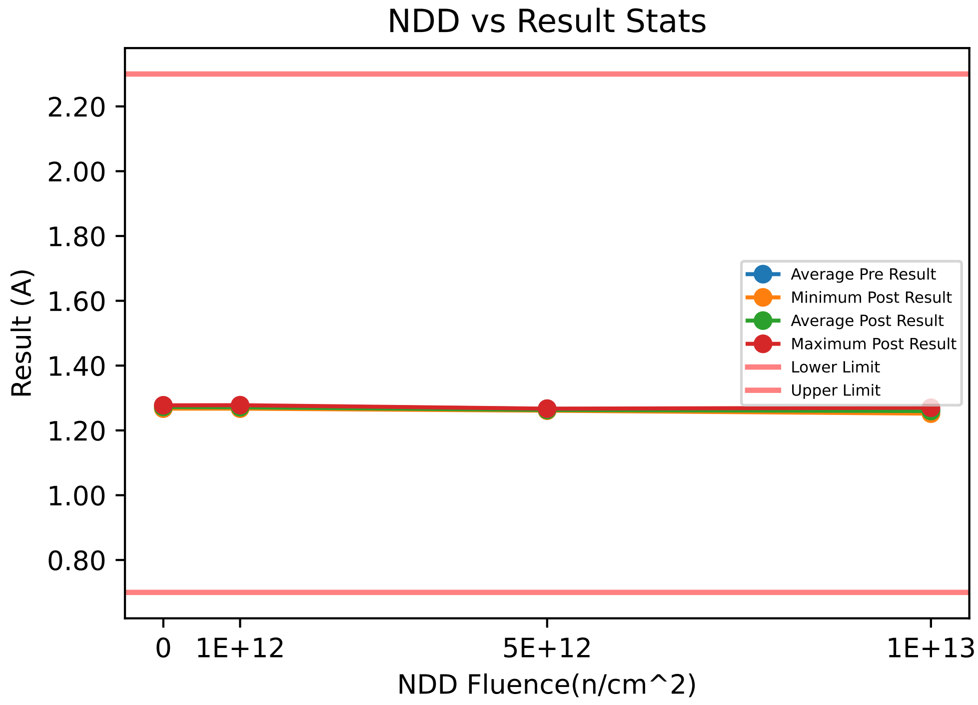
Test Results (Upper Limit = 0.3 (V))

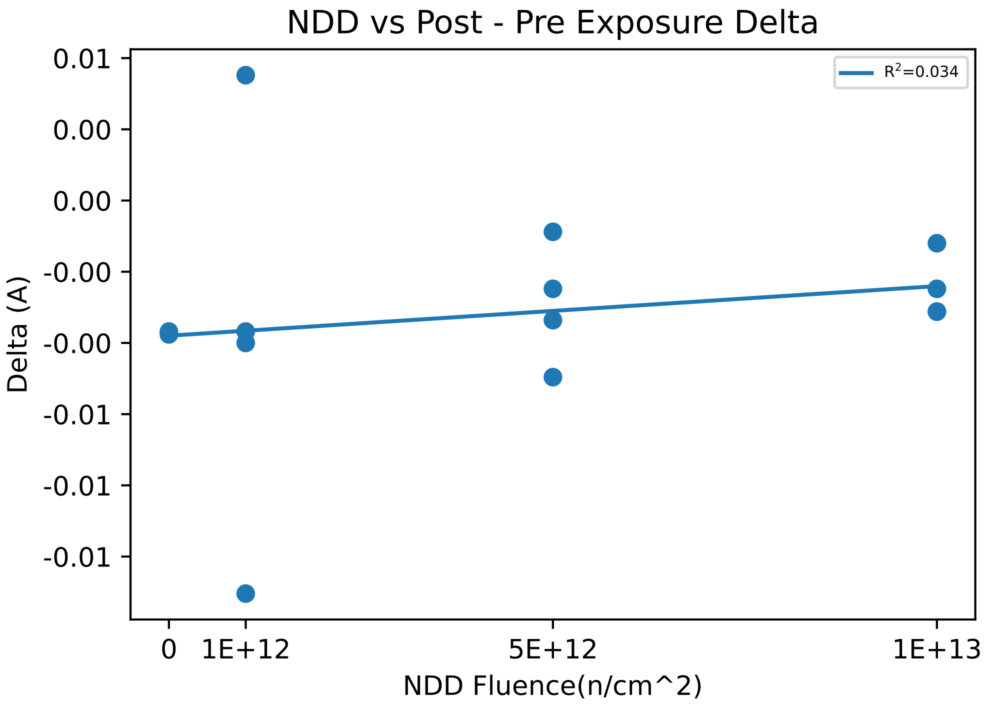
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	0.1245	0.1253	0.0008
2	0	Correlation	0.1255	0.1254	-0.0001
30	1e+12	NDD unbiased	0.1248	0.1273	0.0025
31	1e+12	NDD unbiased	0.1256	0.1255	-0.0001
32	1e+12	NDD unbiased	0.1256	0.1271	0.0015
33	1e+12	NDD unbiased	0.1248	0.1265	0.0017
44	5e+12	NDD unbiased	0.1262	0.1276	0.0014
45	5e+12	NDD unbiased	0.1257	0.1279	0.0022
46	5e+12	NDD unbiased	0.1255	0.1269	0.0014
47	5e+12	NDD unbiased	0.1268	0.128	0.0012
50	1e+13	NDD unbiased	0.1273	0.1291	0.0018
51	1e+13	NDD unbiased	0.1262	0.1278	0.0016
52	1e+13	NDD unbiased	0.1262	0.1285	0.0023
53	1e+13	NDD unbiased	0.1257	0.1278	0.0021

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.1245	0.125	0.1255	0.00070711	0.1253	0.12535	0.1254	7.0711e-05	-0.0001	0.00035	0.0008	0.0006364
1e+12	0.1248	0.1252	0.1256	0.00046188	0.1255	0.1266	0.1273	0.00080829	-0.0001	0.0014	0.0025	0.0010893
5e+12	0.1255	0.12605	0.1268	0.00058023	0.1269	0.1276	0.128	0.00049666	0.0012	0.00155	0.0022	0.00044347
1e+13	0.1257	0.12635	0.1273	0.00067577	0.1278	0.1283	0.1291	0.00062716	0.0016	0.00195	0.0023	0.00031091

Device Test: 50.0 I_OH(_IOH LO VIN_10V)


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

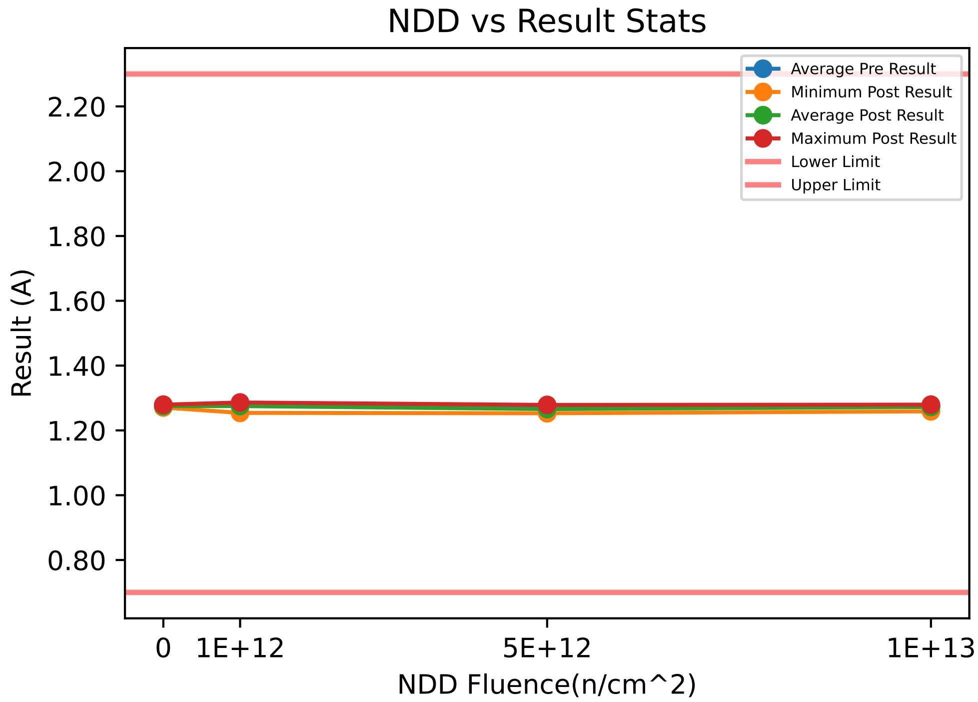
Test Results (Lower Limit = 0.7, Upper Limit = 2.3 (A))

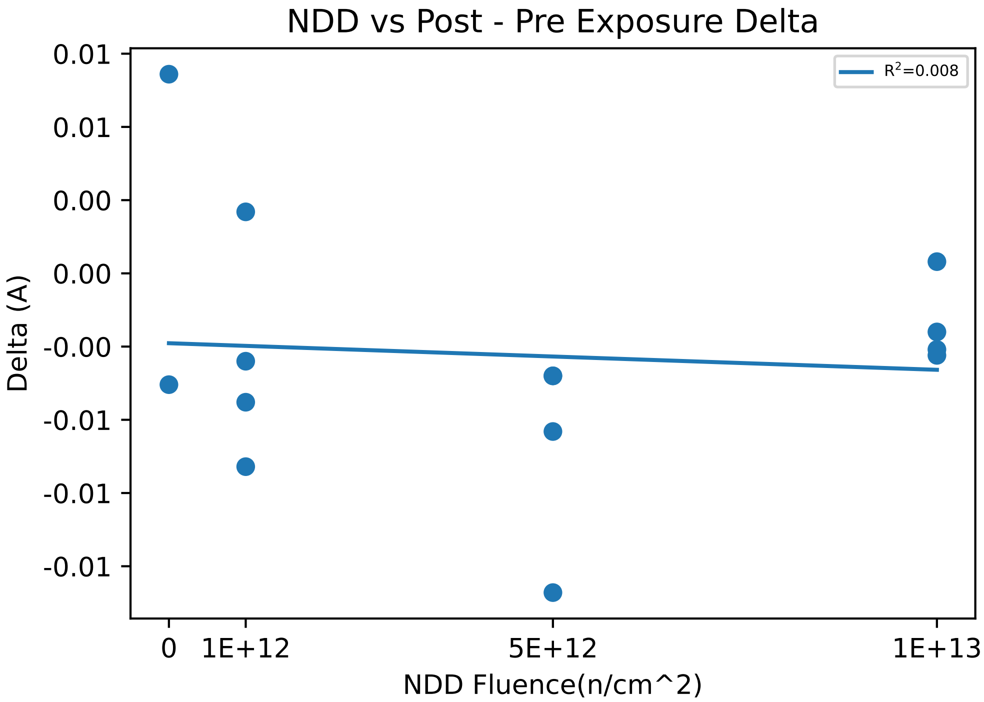
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	1.282	1.2774	-0.0046
2	0	Correlation	1.2718	1.2671	-0.0047
30	1e+12	NDD unbiased	1.2809	1.2671	-0.0138
31	1e+12	NDD unbiased	1.2734	1.2778	0.0044
32	1e+12	NDD unbiased	1.2745	1.2699	-0.0046
33	1e+12	NDD unbiased	1.2761	1.2711	-0.005
44	5e+12	NDD unbiased	1.2674	1.2632	-0.0042
45	5e+12	NDD unbiased	1.267	1.2608	-0.0062
46	5e+12	NDD unbiased	1.2702	1.2671	-0.0031
47	5e+12	NDD unbiased	1.2619	1.2608	-0.0011
50	1e+13	NDD unbiased	1.2556	1.2517	-0.0039
51	1e+13	NDD unbiased	1.2682	1.2643	-0.0039
52	1e+13	NDD unbiased	1.2564	1.2533	-0.0031
53	1e+13	NDD unbiased	1.2714	1.2699	-0.0015

Test Statistics (A)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.2718	1.2769	1.282	0.0072125	1.2671	1.2723	1.2774	0.0072832	-0.0047	-0.00465	-0.0046	7.0711e-05
1e+12	1.2734	1.2762	1.2809	0.0033079	1.2671	1.2715	1.2778	0.0045375	-0.0138	-0.00475	0.0044	0.0074321
5e+12	1.2619	1.2666	1.2702	0.0034568	1.2608	1.263	1.2671	0.0029736	-0.0062	-0.00365	-0.0011	0.0021299
1e+13	1.2556	1.2629	1.2714	0.0080804	1.2517	1.2598	1.2699	0.0087582	-0.0039	-0.0031	-0.0015	0.0011314

Device Test: 50.1 I_OH(_IOH HO VIN_10V)





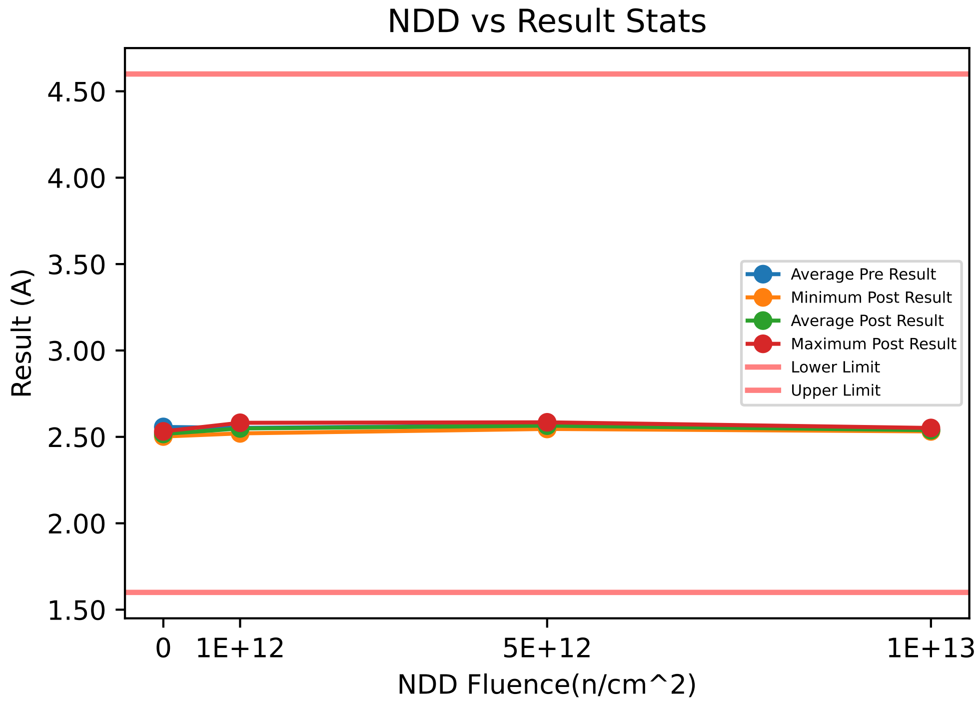
Test Results (Lower Limit = 0.7, Upper Limit = 2.3 (A))

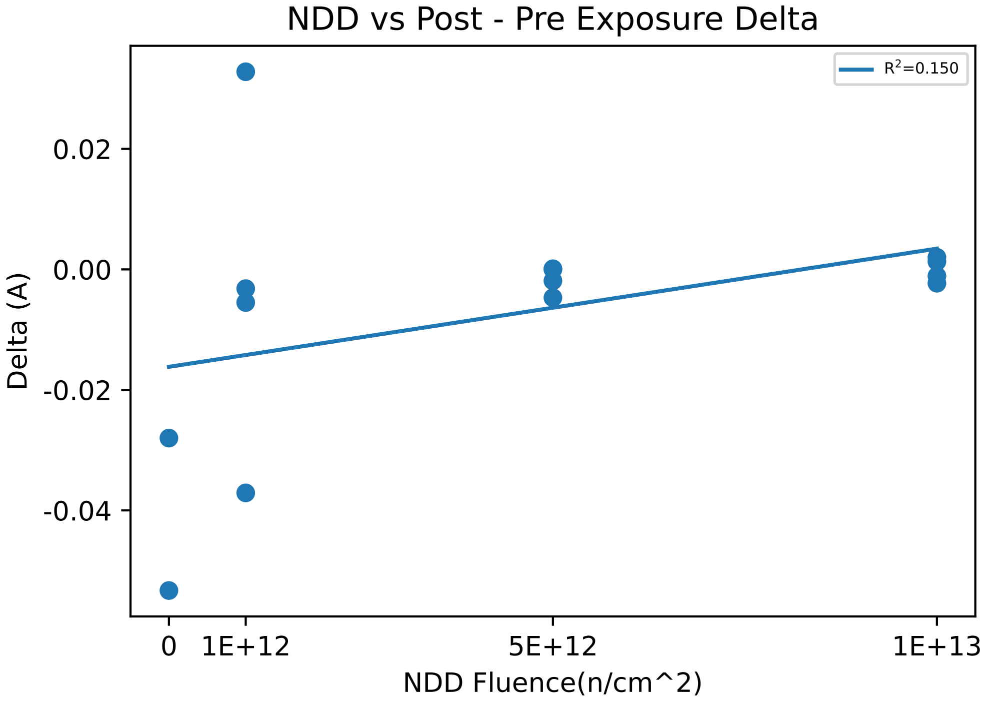
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	1.2832	1.2794	-0.0038
2	0	Correlation	1.2639	1.2707	0.0068
30	1e+12	NDD unbiased	1.2797	1.2818	0.0021
31	1e+12	NDD unbiased	1.2848	1.2782	-0.0066
32	1e+12	NDD unbiased	1.2891	1.2861	-0.003
33	1e+12	NDD unbiased	1.2585	1.2541	-0.0044
44	5e+12	NDD unbiased	1.2564	1.2529	-0.0035
45	5e+12	NDD unbiased	1.2895	1.2786	-0.0109
46	5e+12	NDD unbiased	1.2572	1.2537	-0.0035
47	5e+12	NDD unbiased	1.2836	1.2782	-0.0054
50	1e+13	NDD unbiased	1.2814	1.2794	-0.002
51	1e+13	NDD unbiased	1.282	1.2794	-0.0026
52	1e+13	NDD unbiased	1.2747	1.2719	-0.0028
53	1e+13	NDD unbiased	1.2585	1.2589	0.0004

Test Statistics (A)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.2639	1.2735	1.2832	0.013647	1.2707	1.2751	1.2794	0.0061518	-0.0038	0.0015	0.0068	0.0074953
1e+12	1.2585	1.278	1.2891	0.013572	1.2541	1.2751	1.2861	0.014335	-0.0066	-0.002975	0.0021	0.0036936
5e+12	1.2564	1.2717	1.2895	0.017347	1.2529	1.2658	1.2786	0.014496	-0.0109	-0.005825	-0.0035	0.0034999
1e+13	1.2585	1.2742	1.282	0.010945	1.2589	1.2724	1.2794	0.0096695	-0.0028	-0.00175	0.0004	0.0014731

Device Test: 50.2 I_OL(_IOL LO VIN_10V)





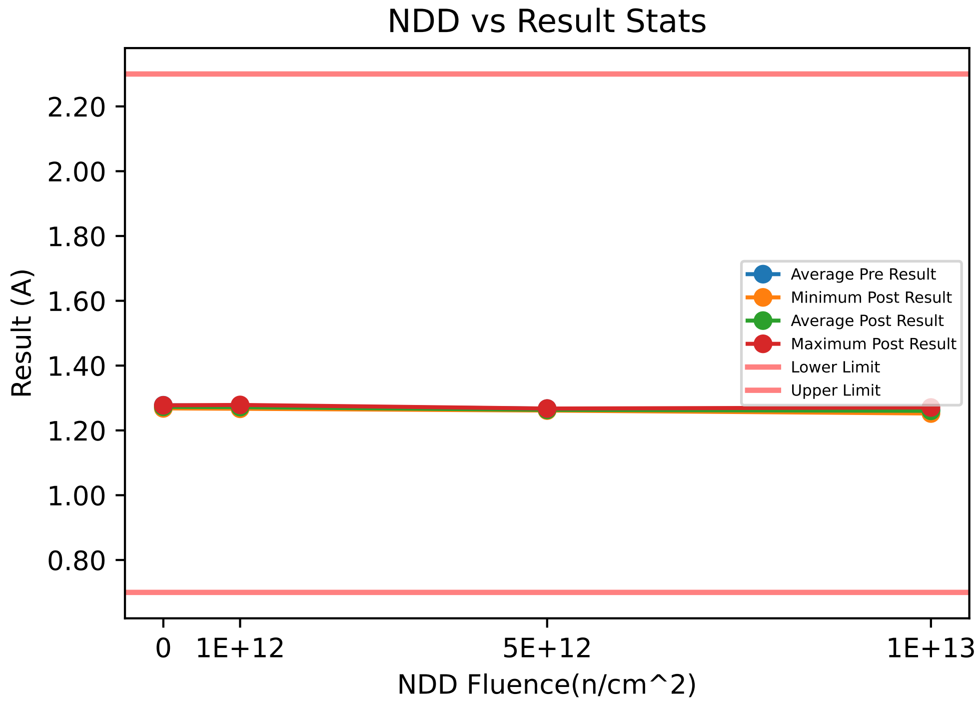
Test Results (Lower Limit = 1.6, Upper Limit = 4.6 (A))

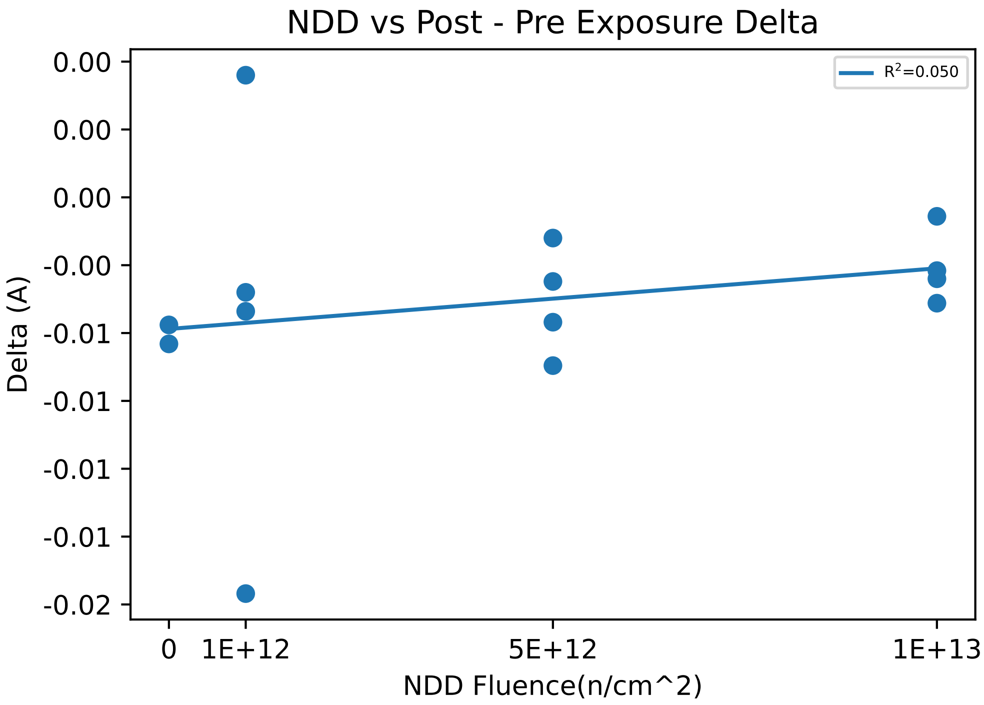
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	2.5597	2.5317	-0.028
2	0	Correlation	2.5554	2.5021	-0.0533
30	1e+12	NDD unbiased	2.5664	2.5293	-0.0371
31	1e+12	NDD unbiased	2.5309	2.5637	0.0328
32	1e+12	NDD unbiased	2.5234	2.5202	-0.0032
33	1e+12	NDD unbiased	2.587	2.5815	-0.0055
44	5e+12	NDD unbiased	2.5842	2.5823	-0.0019
45	5e+12	NDD unbiased	2.5518	2.5471	-0.0047
46	5e+12	NDD unbiased	2.5842	2.5843	0.0001
47	5e+12	NDD unbiased	2.5459	2.5459	0
50	1e+13	NDD unbiased	2.5324	2.5337	0.0013
51	1e+13	NDD unbiased	2.536	2.538	0.002
52	1e+13	NDD unbiased	2.5328	2.5317	-0.0011
53	1e+13	NDD unbiased	2.5538	2.5515	-0.0023

Test Statistics (A)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.5554	2.5575	2.5597	0.0030406	2.5021	2.5169	2.5317	0.02093	-0.0533	-0.04065	-0.028	0.01789
1e+12	2.5234	2.5519	2.587	0.029975	2.5202	2.5487	2.5815	0.028807	-0.0371	-0.00325	0.0328	0.02858
5e+12	2.5459	2.5665	2.5842	0.020551	2.5459	2.5649	2.5843	0.021268	-0.0047	-0.001625	0.0001	0.002247
1e+13	2.5324	2.5387	2.5538	0.010162	2.5317	2.5387	2.5515	0.0089131	-0.0023	-2.5e-05	0.002	0.0020156

Device Test: 51.0 I_OH(_IOH LO VIN_12V)





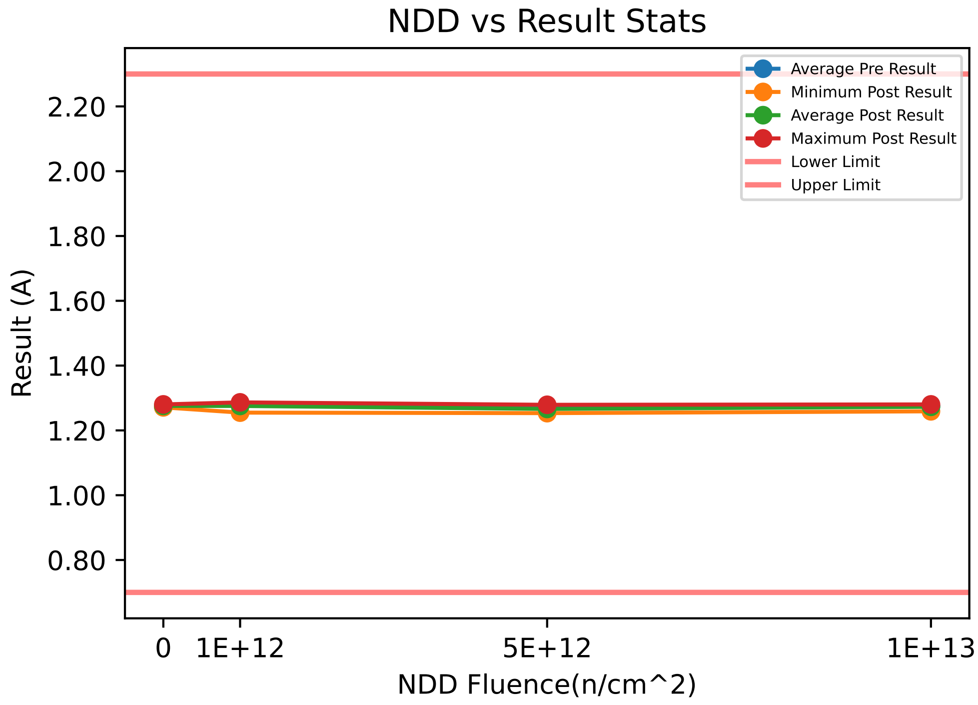
Test Results (Lower Limit = 0.7, Upper Limit = 2.3 (A))

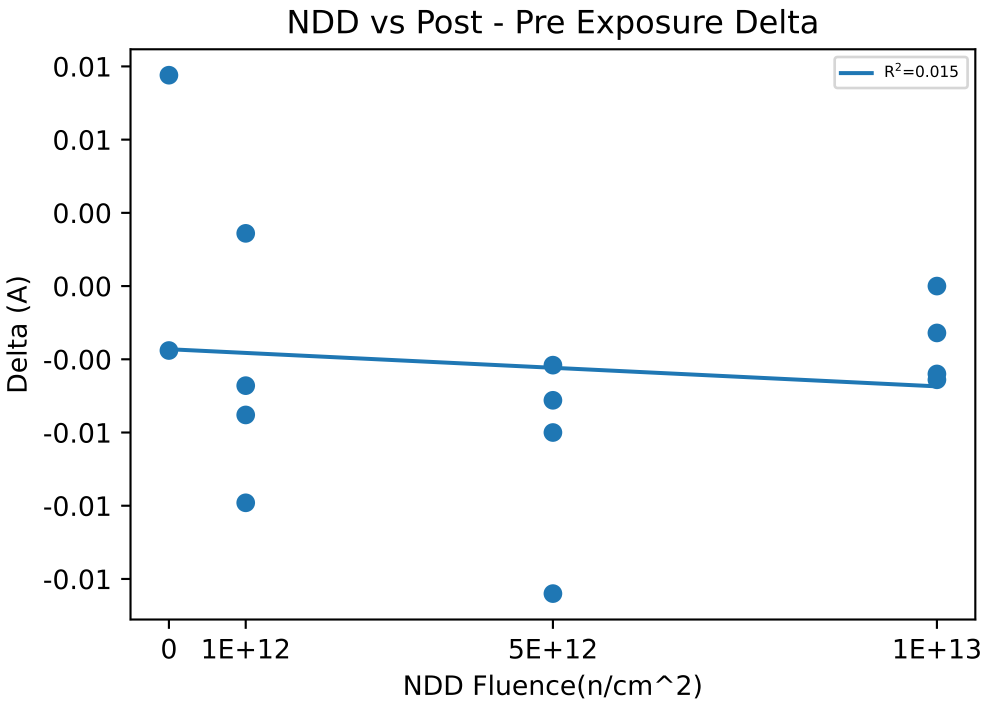
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	1.2828	1.2774	-0.0054
2	0	Correlation	1.2726	1.2679	-0.0047
30	1e+12	NDD unbiased	1.2813	1.2667	-0.0146
31	1e+12	NDD unbiased	1.2741	1.2786	0.0045
32	1e+12	NDD unbiased	1.2745	1.2703	-0.0042
33	1e+12	NDD unbiased	1.2753	1.2718	-0.0035
44	5e+12	NDD unbiased	1.2678	1.2632	-0.0046
45	5e+12	NDD unbiased	1.2678	1.2616	-0.0062
46	5e+12	NDD unbiased	1.2706	1.2675	-0.0031
47	5e+12	NDD unbiased	1.2627	1.2612	-0.0015
50	1e+13	NDD unbiased	1.2548	1.2521	-0.0027
51	1e+13	NDD unbiased	1.2686	1.2647	-0.0039
52	1e+13	NDD unbiased	1.2571	1.2541	-0.003
53	1e+13	NDD unbiased	1.2714	1.2707	-0.0007

Test Statistics (A)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.2726	1.2777	1.2828	0.0072125	1.2679	1.2727	1.2774	0.0067175	-0.0054	-0.00505	-0.0047	0.00049497
1e+12	1.2741	1.2763	1.2813	0.0033705	1.2667	1.2718	1.2786	0.004983	-0.0146	-0.00445	0.0045	0.0078335
5e+12	1.2627	1.2672	1.2706	0.0032928	1.2612	1.2634	1.2675	0.0028826	-0.0062	-0.00385	-0.0015	0.0020141
1e+13	1.2548	1.263	1.2714	0.0082456	1.2521	1.2604	1.2707	0.0088159	-0.0039	-0.002575	-0.0007	0.00135

Device Test: 51.1 I_OH(_IOH HO VIN_12V)





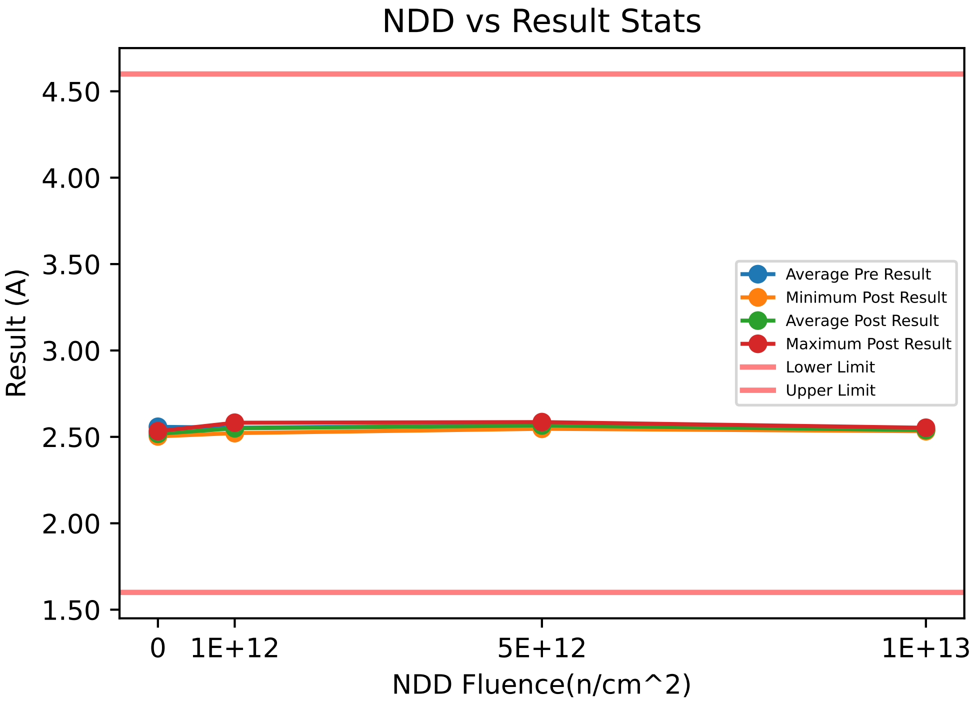
Test Results (Lower Limit = 0.7, Upper Limit = 2.3 (A))

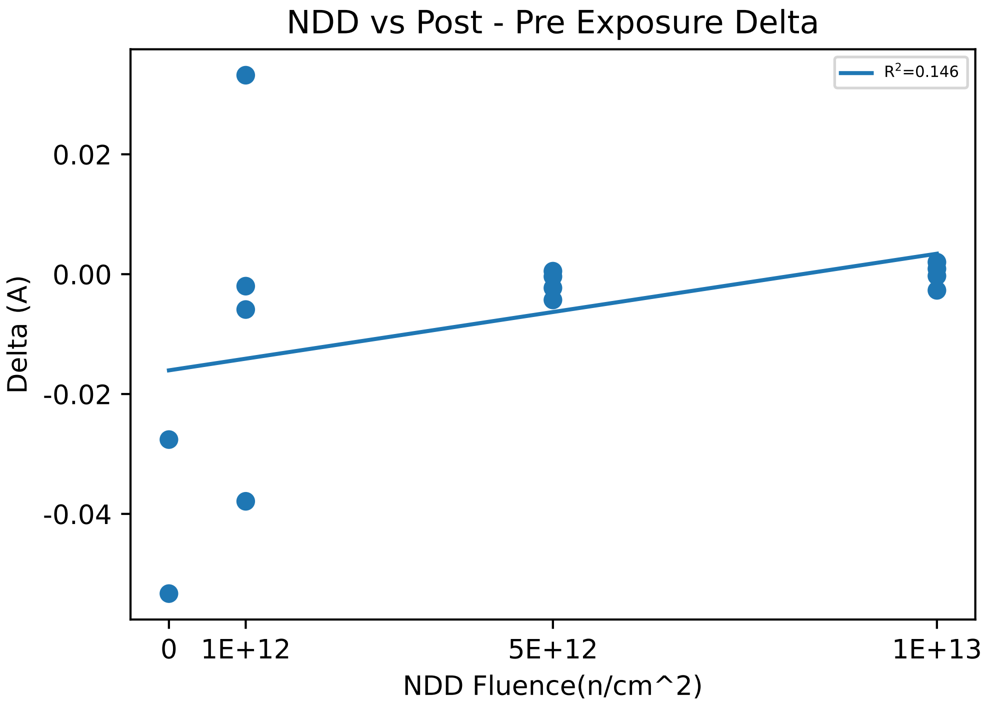
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	1.2824	1.2802	-0.0022
2	0	Correlation	1.2639	1.2711	0.0072
30	1e+12	NDD unbiased	1.2804	1.2822	0.0018
31	1e+12	NDD unbiased	1.2856	1.2782	-0.0074
32	1e+12	NDD unbiased	1.2899	1.2865	-0.0034
33	1e+12	NDD unbiased	1.2593	1.2549	-0.0044
44	5e+12	NDD unbiased	1.256	1.2533	-0.0027
45	5e+12	NDD unbiased	1.2895	1.279	-0.0105
46	5e+12	NDD unbiased	1.2576	1.2537	-0.0039
47	5e+12	NDD unbiased	1.284	1.279	-0.005
50	1e+13	NDD unbiased	1.2814	1.2798	-0.0016
51	1e+13	NDD unbiased	1.2832	1.2802	-0.003
52	1e+13	NDD unbiased	1.2755	1.2723	-0.0032
53	1e+13	NDD unbiased	1.2589	1.2589	0

Test Statistics (A)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.2639	1.2732	1.2824	0.013081	1.2711	1.2756	1.2802	0.0064347	-0.0022	0.0025	0.0072	0.0066468
1e+12	1.2593	1.2788	1.2899	0.013568	1.2549	1.2754	1.2865	0.014113	-0.0074	-0.00335	0.0018	0.003831
5e+12	1.256	1.2718	1.2895	0.017449	1.2533	1.2662	1.279	0.014723	-0.0105	-0.005525	-0.0027	0.0034471
1e+13	1.2589	1.2748	1.2832	0.011067	1.2589	1.2728	1.2802	0.0099536	-0.0032	-0.00195	0	0.0014821

Device Test: 51.2 I_OL(_IOL LO VIN_12V)





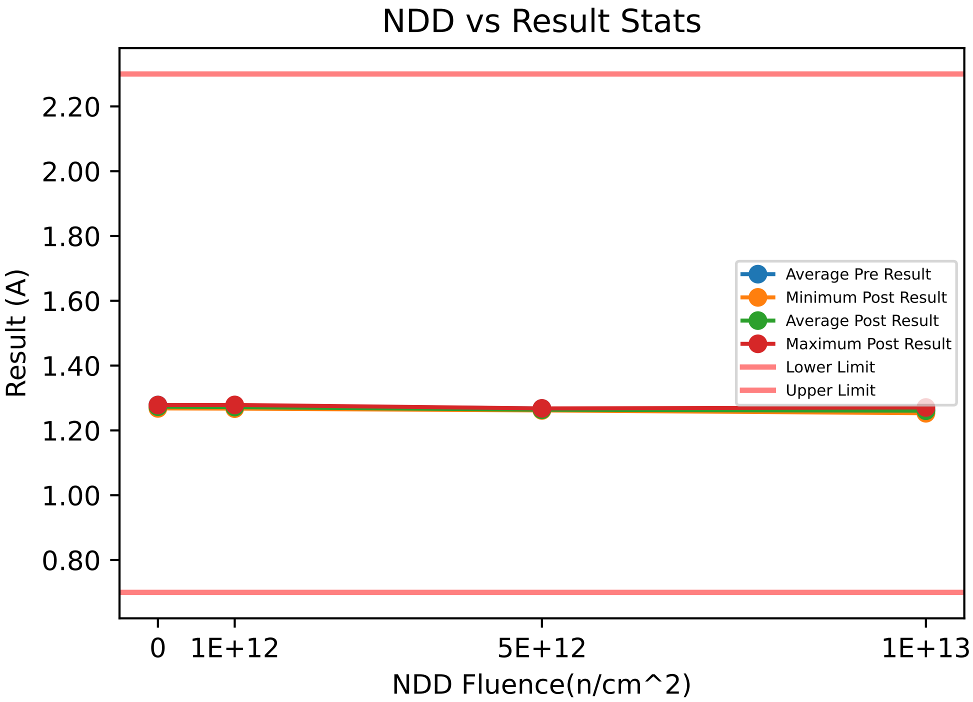
Test Results (Lower Limit = 1.6, Upper Limit = 4.6 (A))

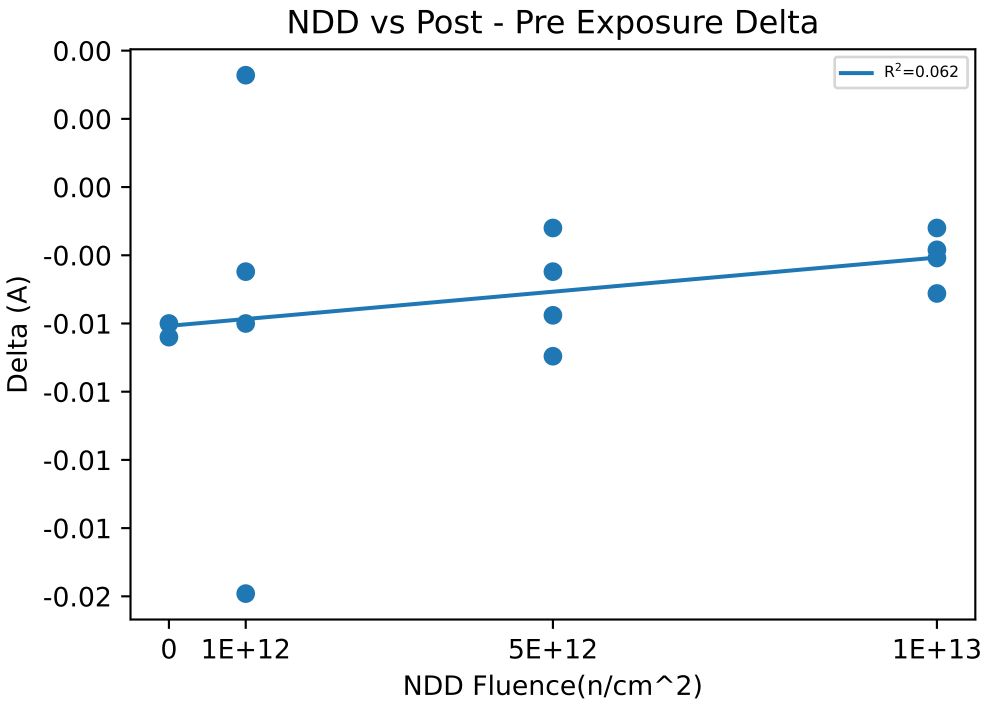
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	2.5605	2.5329	-0.0276
2	0	Correlation	2.5562	2.5029	-0.0533
30	1e+12	NDD unbiased	2.5676	2.5297	-0.0379
31	1e+12	NDD unbiased	2.5317	2.5649	0.0332
32	1e+12	NDD unbiased	2.5238	2.5218	-0.002
33	1e+12	NDD unbiased	2.5878	2.5819	-0.0059
44	5e+12	NDD unbiased	2.5858	2.5835	-0.0023
45	5e+12	NDD unbiased	2.5526	2.5483	-0.0043
46	5e+12	NDD unbiased	2.585	2.5855	0.0005
47	5e+12	NDD unbiased	2.5471	2.5467	-0.0004
50	1e+13	NDD unbiased	2.5336	2.5345	0.0009
51	1e+13	NDD unbiased	2.5368	2.5388	0.002
52	1e+13	NDD unbiased	2.5332	2.5329	-0.0003
53	1e+13	NDD unbiased	2.5554	2.5527	-0.0027

Test Statistics (A)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.5562	2.5583	2.5605	0.0030406	2.5029	2.5179	2.5329	0.021213	-0.0533	-0.04045	-0.0276	0.018173
1e+12	2.5238	2.5527	2.5878	0.030167	2.5218	2.5496	2.5819	0.028555	-0.0379	-0.00315	0.0332	0.029085
5e+12	2.5471	2.5676	2.5858	0.02065	2.5467	2.566	2.5855	0.021388	-0.0043	-0.001625	0.0005	0.0021313
1e+13	2.5332	2.5397	2.5554	0.010557	2.5329	2.5397	2.5527	0.0090016	-0.0027	-2.5e-05	0.002	0.0020156

Device Test: 52.0 I_OH(_IOH LO VIN_14V)





Test Results (Lower Limit = 0.7, Upper Limit = 2.3 (A))

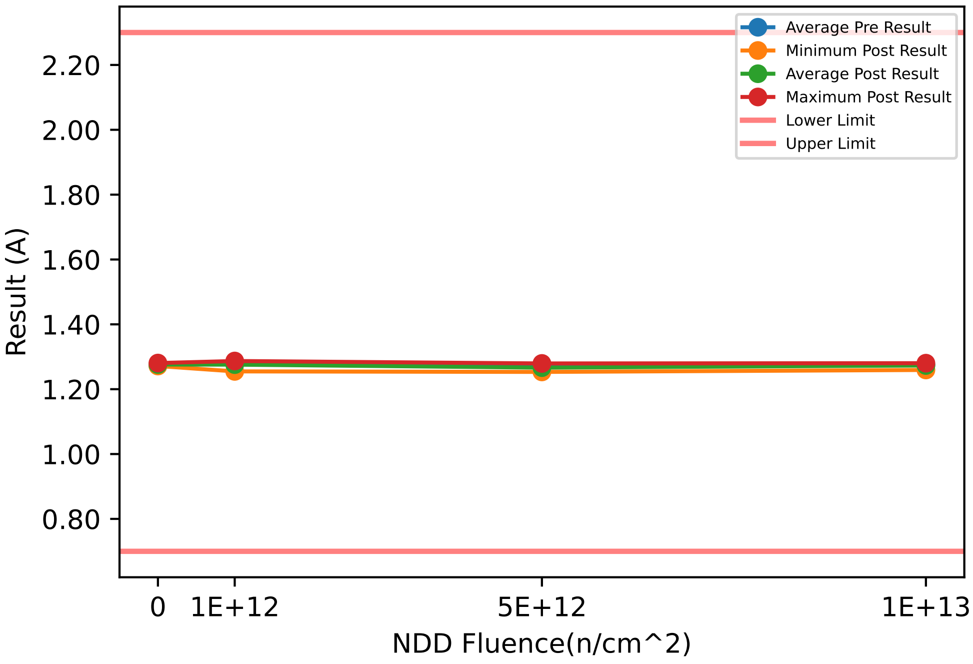
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	1.2832	1.2782	-0.005
2	0	Correlation	1.2734	1.2679	-0.0055
30	1e+12	NDD unbiased	1.282	1.2671	-0.0149
31	1e+12	NDD unbiased	1.2745	1.2786	0.0041
32	1e+12	NDD unbiased	1.2753	1.2703	-0.005
33	1e+12	NDD unbiased	1.2749	1.2718	-0.0031
44	5e+12	NDD unbiased	1.2682	1.2635	-0.0047
45	5e+12	NDD unbiased	1.2678	1.2616	-0.0062
46	5e+12	NDD unbiased	1.271	1.2679	-0.0031
47	5e+12	NDD unbiased	1.2631	1.2616	-0.0015
50	1e+13	NDD unbiased	1.2552	1.2529	-0.0023
51	1e+13	NDD unbiased	1.269	1.2651	-0.0039
52	1e+13	NDD unbiased	1.2567	1.2541	-0.0026
53	1e+13	NDD unbiased	1.2722	1.2707	-0.0015

Test Statistics (A)

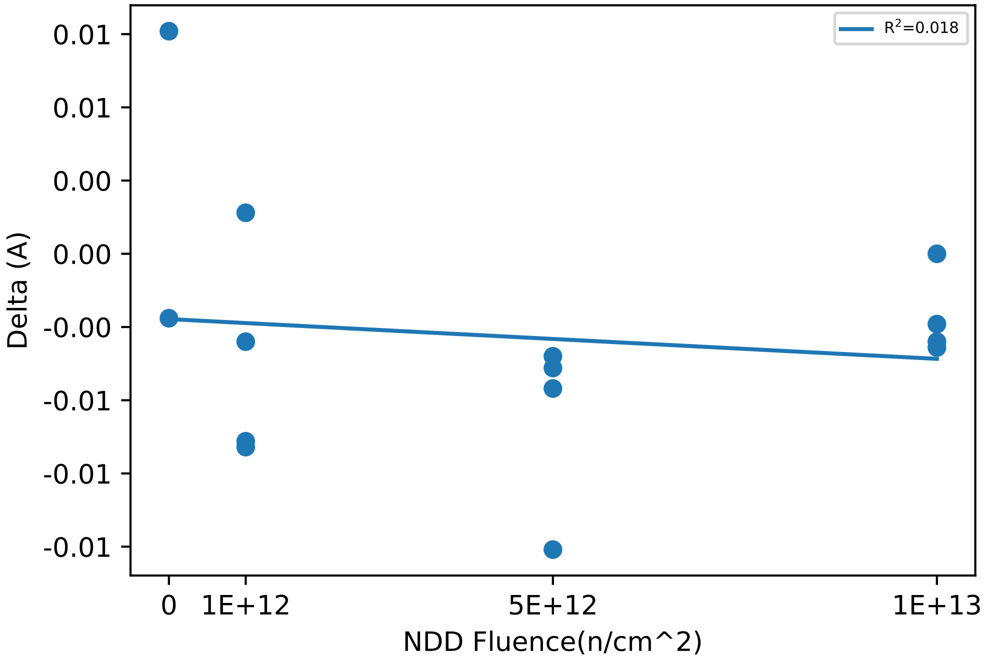
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.2734	1.2783	1.2832	0.0069296	1.2679	1.2731	1.2782	0.0072832	-0.0055	-0.00525	-0.005	0.00035355
1e+12	1.2745	1.2767	1.282	0.003565	1.2671	1.2719	1.2786	0.0048473	-0.0149	-0.004725	0.0041	0.0078343
5e+12	1.2631	1.2675	1.271	0.0032755	1.2616	1.2637	1.2679	0.0029715	-0.0062	-0.003875	-0.0015	0.0020271
1e+13	1.2552	1.2633	1.2722	0.0085804	1.2529	1.2607	1.2707	0.0086364	-0.0039	-0.002575	-0.0015	0.00099791

Device Test: 52.1 I_OH(_IOH HO VIN_14V)

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



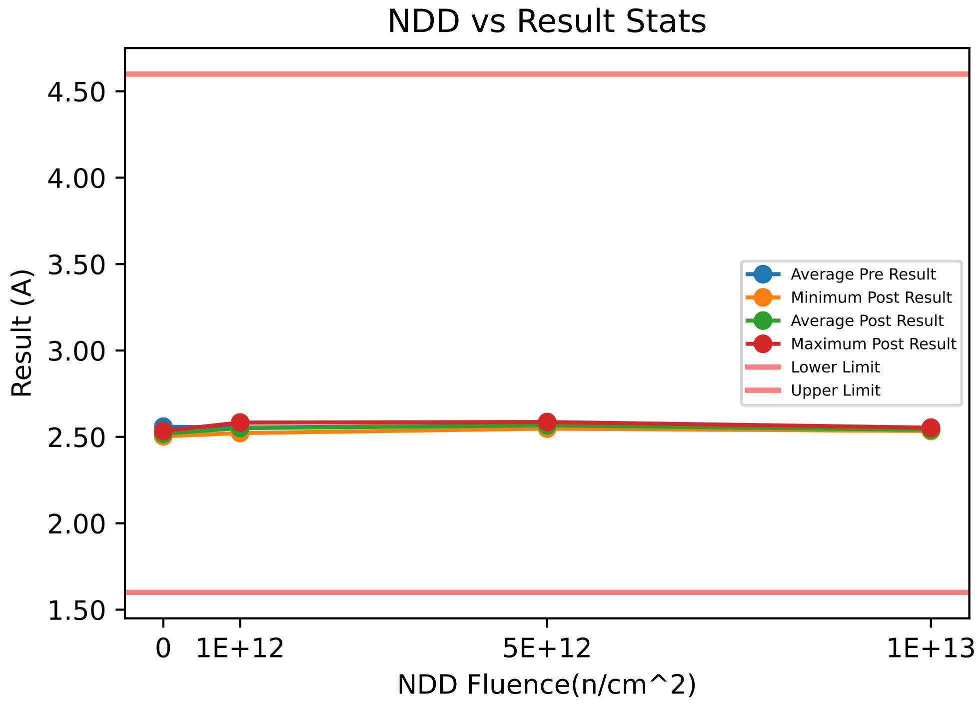
Test Results (Lower Limit = 0.7, Upper Limit = 2.3 (A))

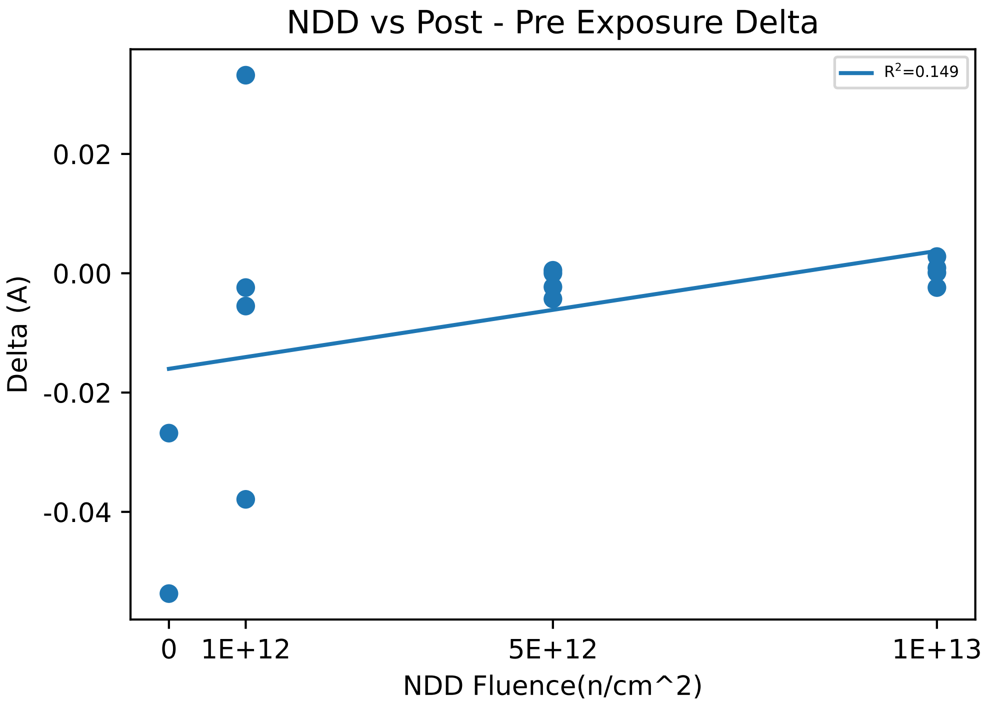
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	1.2828	1.2806	-0.0022
2	0	Correlation	1.2639	1.2715	0.0076
30	1e+12	NDD unbiased	1.2808	1.2822	0.0014
31	1e+12	NDD unbiased	1.2856	1.279	-0.0066
32	1e+12	NDD unbiased	1.2899	1.2869	-0.003
33	1e+12	NDD unbiased	1.2613	1.2549	-0.0064
44	5e+12	NDD unbiased	1.2568	1.2533	-0.0035
45	5e+12	NDD unbiased	1.2895	1.2794	-0.0101
46	5e+12	NDD unbiased	1.2576	1.2537	-0.0039
47	5e+12	NDD unbiased	1.284	1.2794	-0.0046
50	1e+13	NDD unbiased	1.2826	1.2802	-0.0024
51	1e+13	NDD unbiased	1.2832	1.2802	-0.003
52	1e+13	NDD unbiased	1.2759	1.2727	-0.0032
53	1e+13	NDD unbiased	1.2593	1.2593	0

Test Statistics (A)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.2639	1.2733	1.2828	0.013364	1.2715	1.2761	1.2806	0.0064347	-0.0022	0.0027	0.0076	0.0069296
1e+12	1.2613	1.2794	1.2899	0.012626	1.2549	1.2757	1.2869	0.014274	-0.0066	-0.00365	0.0014	0.0037501
5e+12	1.2568	1.272	1.2895	0.017211	1.2533	1.2665	1.2794	0.014954	-0.0101	-0.005525	-0.0035	0.0030837
1e+13	1.2593	1.2752	1.2832	0.011136	1.2593	1.2731	1.2802	0.009856	-0.0032	-0.00215	0	0.0014731

Device Test: 52.2 I_OL(_IOL LO VIN_14V)





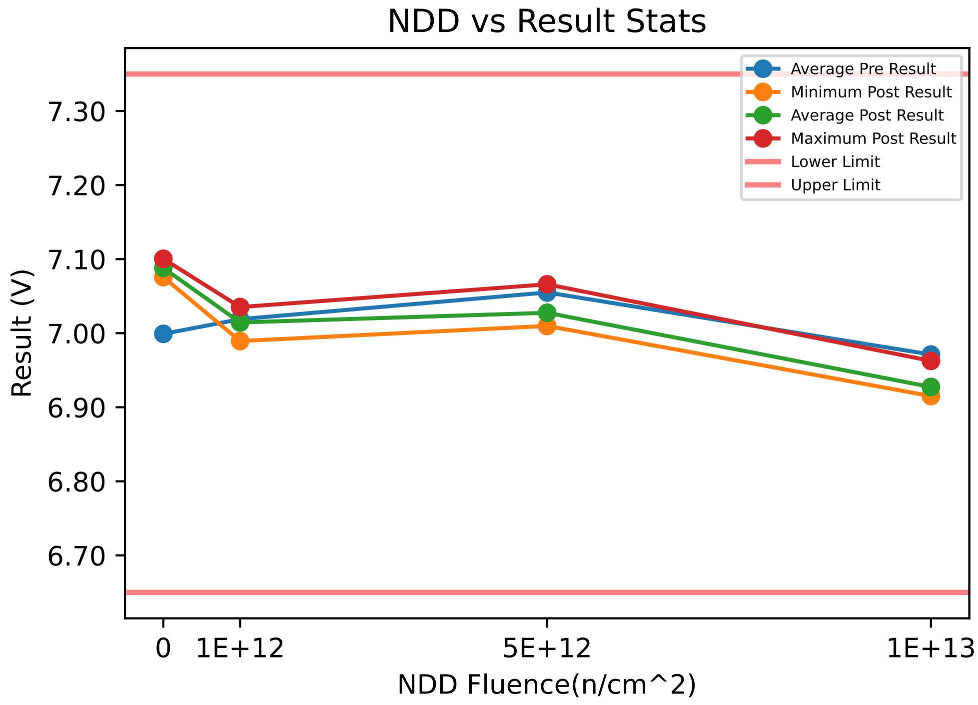
Test Results (Lower Limit = 1.6, Upper Limit = 4.6 (A))

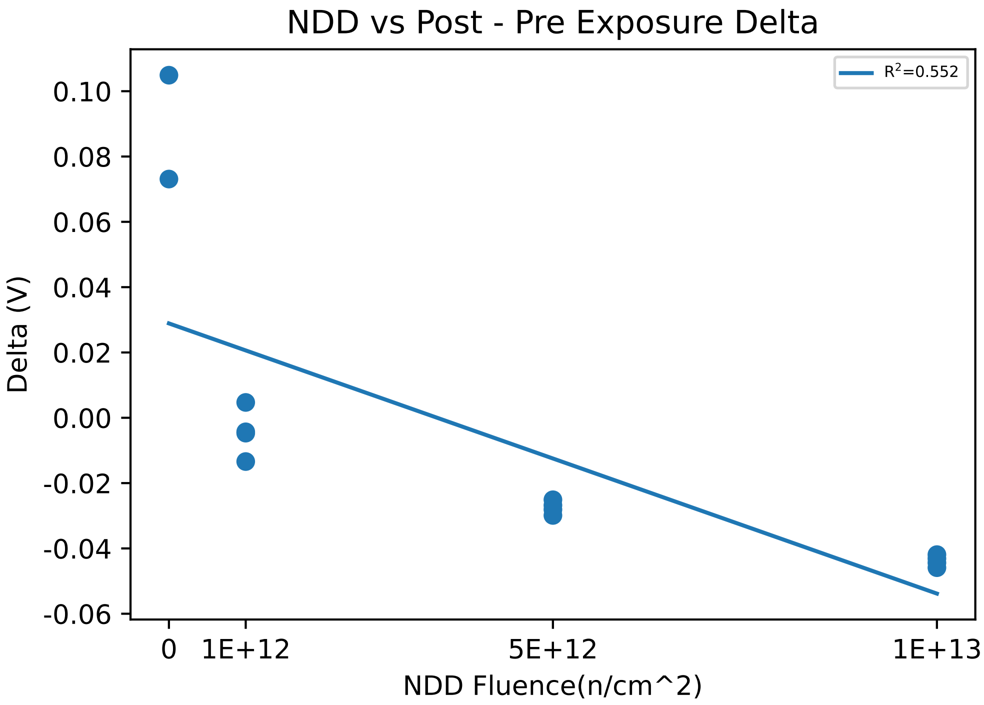
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	2.5609	2.5341	-0.0268
2	0	Correlation	2.5573	2.5036	-0.0537
30	1e+12	NDD unbiased	2.5688	2.5309	-0.0379
31	1e+12	NDD unbiased	2.5325	2.5657	0.0332
32	1e+12	NDD unbiased	2.5246	2.5222	-0.0024
33	1e+12	NDD unbiased	2.5886	2.5831	-0.0055
44	5e+12	NDD unbiased	2.5862	2.5839	-0.0023
45	5e+12	NDD unbiased	2.5534	2.5491	-0.0043
46	5e+12	NDD unbiased	2.5854	2.5859	0.0005
47	5e+12	NDD unbiased	2.5479	2.5479	0
50	1e+13	NDD unbiased	2.5348	2.5357	0.0009
51	1e+13	NDD unbiased	2.5376	2.5404	0.0028
52	1e+13	NDD unbiased	2.534	2.5341	0.0001
53	1e+13	NDD unbiased	2.5558	2.5534	-0.0024

Test Statistics (A)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.5573	2.5591	2.5609	0.0025456	2.5036	2.5189	2.5341	0.021567	-0.0537	-0.04025	-0.0268	0.019021
1e+12	2.5246	2.5536	2.5886	0.030234	2.5222	2.5505	2.5831	0.028745	-0.0379	-0.00315	0.0332	0.029069
5e+12	2.5479	2.5682	2.5862	0.02042	2.5479	2.5667	2.5859	0.021037	-0.0043	-0.001525	0.0005	0.0022157
1e+13	2.534	2.5406	2.5558	0.010283	2.5341	2.5409	2.5534	0.0087518	-0.0024	0.00035	0.0028	0.0021548

Device Test: 60.0 V_BP7L(_V_BP7L PWM 500kHz VIN_10V)


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

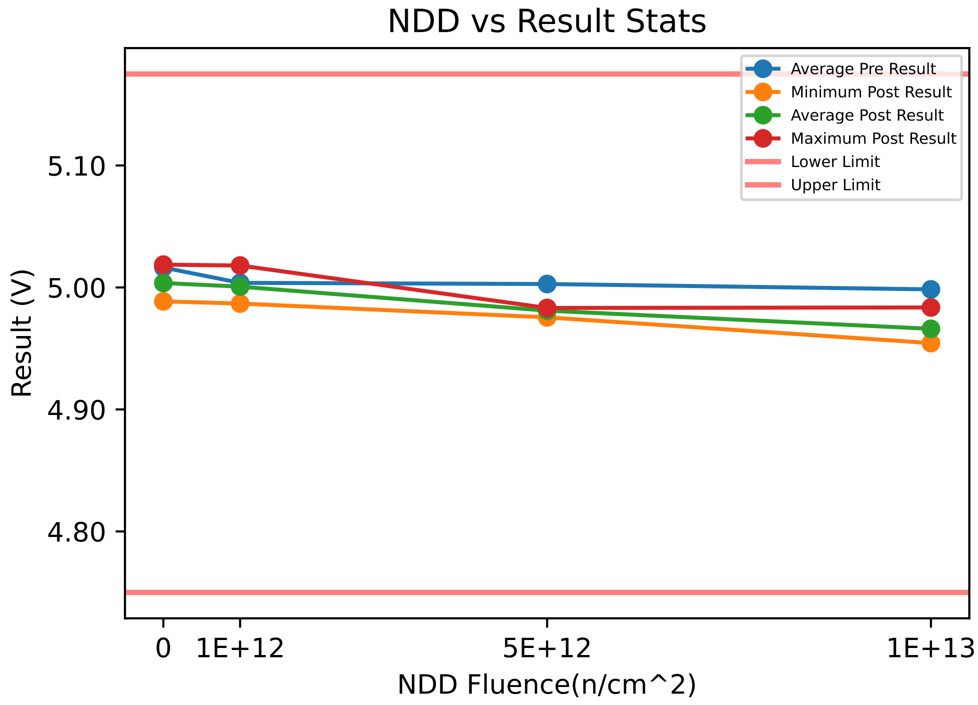
Test Results (Lower Limit = 6.65, Upper Limit = 7.35 (V))

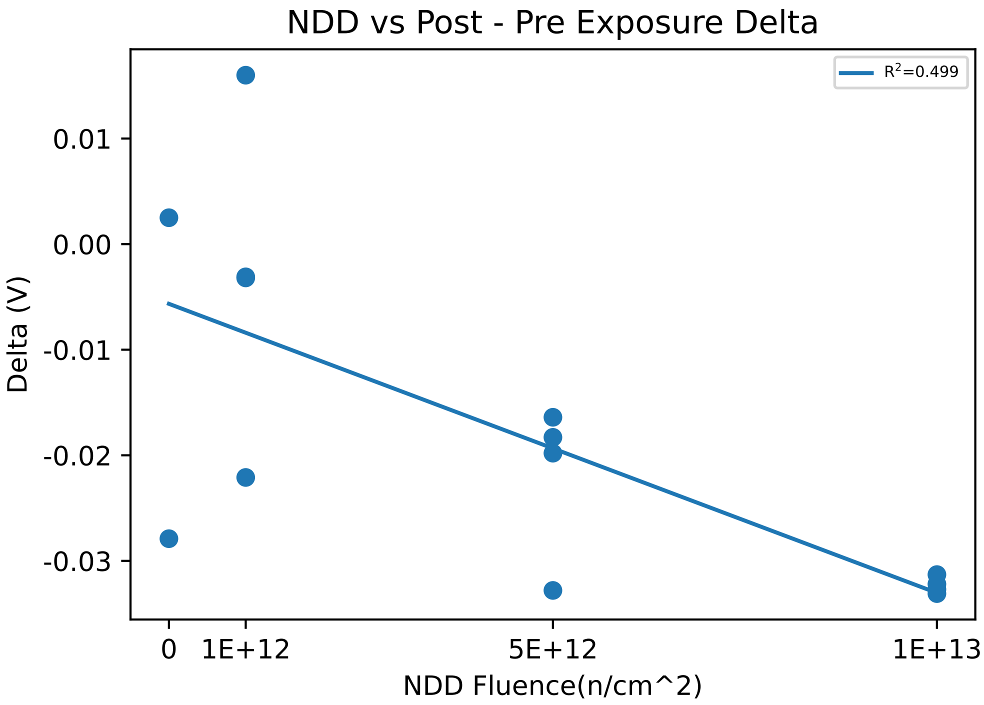
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	7.0026	7.0757	0.0731
2	0	Correlation	6.9956	7.1005	0.1049
30	1e+12	NDD unbiased	7.0306	7.0353	0.0047
31	1e+12	NDD unbiased	7.0397	7.0263	-0.0134
32	1e+12	NDD unbiased	6.9941	6.9894	-0.0047
33	1e+12	NDD unbiased	7.0113	7.007	-0.0043
44	5e+12	NDD unbiased	7.0496	7.0245	-0.0251
45	5e+12	NDD unbiased	7.0398	7.0099	-0.0299
46	5e+12	NDD unbiased	7.0928	7.066	-0.0268
47	5e+12	NDD unbiased	7.0379	7.0098	-0.0281
50	1e+13	NDD unbiased	6.9575	6.9156	-0.0419
51	1e+13	NDD unbiased	6.9595	6.9151	-0.0444
52	1e+13	NDD unbiased	6.9593	6.9162	-0.0431
53	1e+13	NDD unbiased	7.0085	6.9626	-0.0459

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	6.9956	6.9991	7.0026	0.0049497	7.0757	7.0881	7.1005	0.017536	0.0731	0.089	0.1049	0.022486
1e+12	6.9941	7.0189	7.0397	0.02035	6.9894	7.0145	7.0353	0.020479	-0.0134	-0.004425	0.0047	0.0073916
5e+12	7.0379	7.055	7.0928	0.0257	7.0098	7.0275	7.066	0.026547	-0.0299	-0.027475	-0.0251	0.0020304
1e+13	6.9575	6.9712	7.0085	0.024883	6.9151	6.9274	6.9626	0.023488	-0.0459	-0.043825	-0.0419	0.0017193

Device Test: 60.1 V_BP5L(_V_BP5L PWM 500kHz VIN_10V)


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

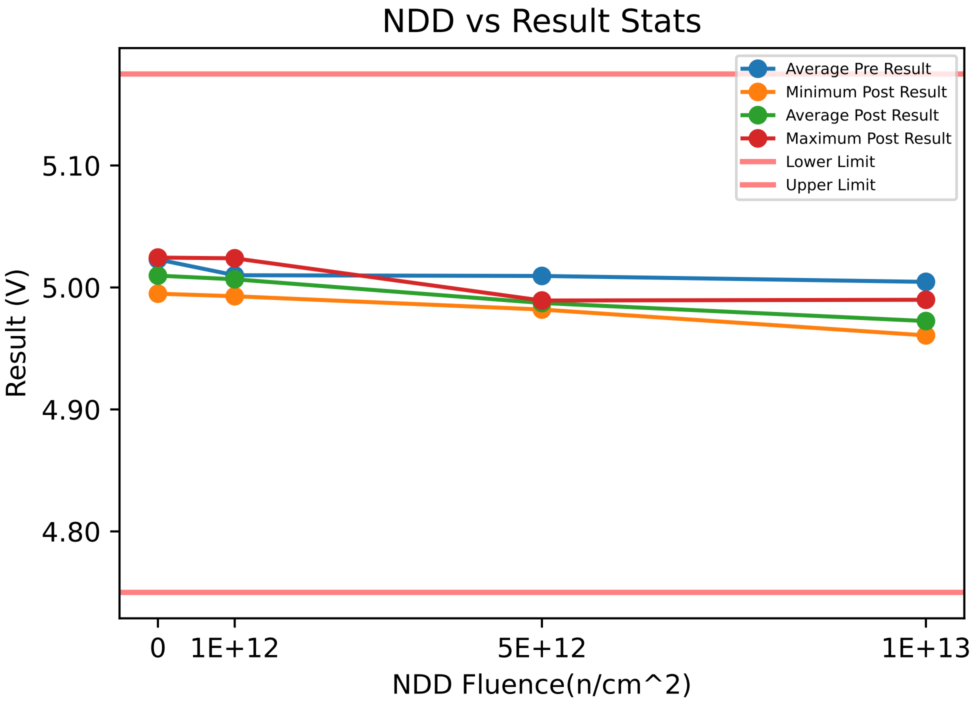
Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

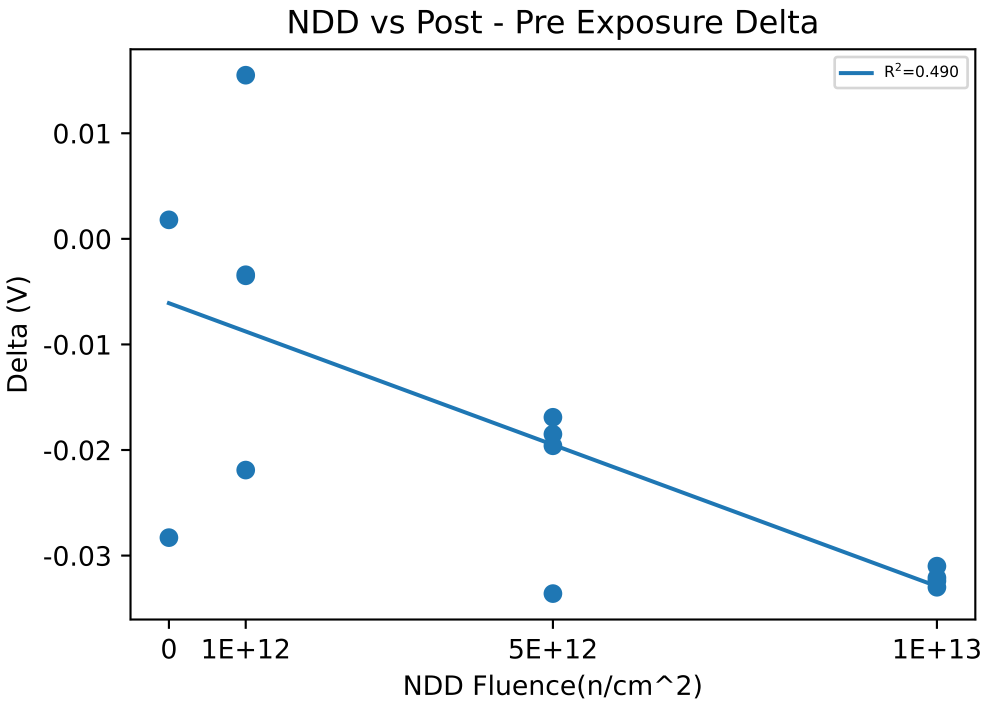
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	5.0165	4.9886	-0.0279
2	0	Correlation	5.0162	5.0187	0.0025
30	1e+12	NDD unbiased	5.0214	4.9993	-0.0221
31	1e+12	NDD unbiased	5.002	5.018	0.016
32	1e+12	NDD unbiased	5.0018	4.9986	-0.0032
33	1e+12	NDD unbiased	4.9899	4.9868	-0.0031
44	5e+12	NDD unbiased	4.9919	4.9755	-0.0164
45	5e+12	NDD unbiased	5.016	4.9832	-0.0328
46	5e+12	NDD unbiased	5.0006	4.9823	-0.0183
47	5e+12	NDD unbiased	5.0028	4.983	-0.0198
50	1e+13	NDD unbiased	4.9866	4.9544	-0.0322
51	1e+13	NDD unbiased	4.9986	4.9659	-0.0327
52	1e+13	NDD unbiased	5.0149	4.9836	-0.0313
53	1e+13	NDD unbiased	4.9936	4.9605	-0.0331

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.0162	5.0164	5.0165	0.00021213	4.9886	5.0037	5.0187	0.021284	-0.0279	-0.0127	0.0025	0.021496
1e+12	4.9899	5.0038	5.0214	0.013041	4.9868	5.0007	5.018	0.012895	-0.0221	-0.0031	0.016	0.015554
5e+12	4.9919	5.0028	5.016	0.0099647	4.9755	4.981	4.9832	0.0036869	-0.0328	-0.021825	-0.0164	0.0074478
1e+13	4.9866	4.9984	5.0149	0.012036	4.9544	4.9661	4.9836	0.012577	-0.0331	-0.032325	-0.0313	0.00077621

Device Test: 60.10 V_BP5L(_V_BP5L PWM 5MHz VIN_10V)





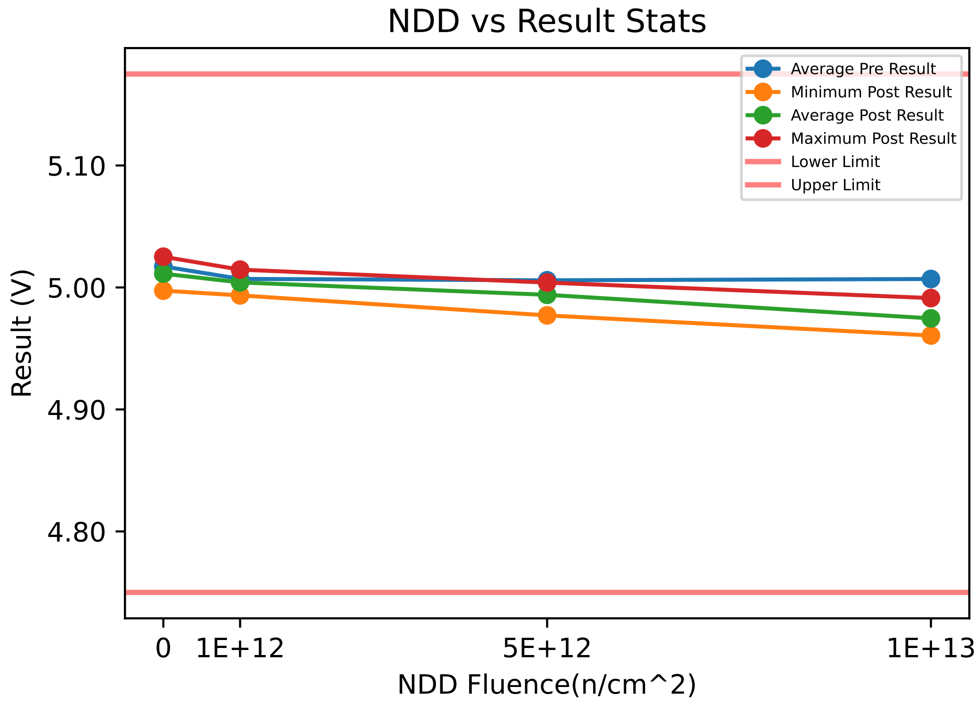
Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

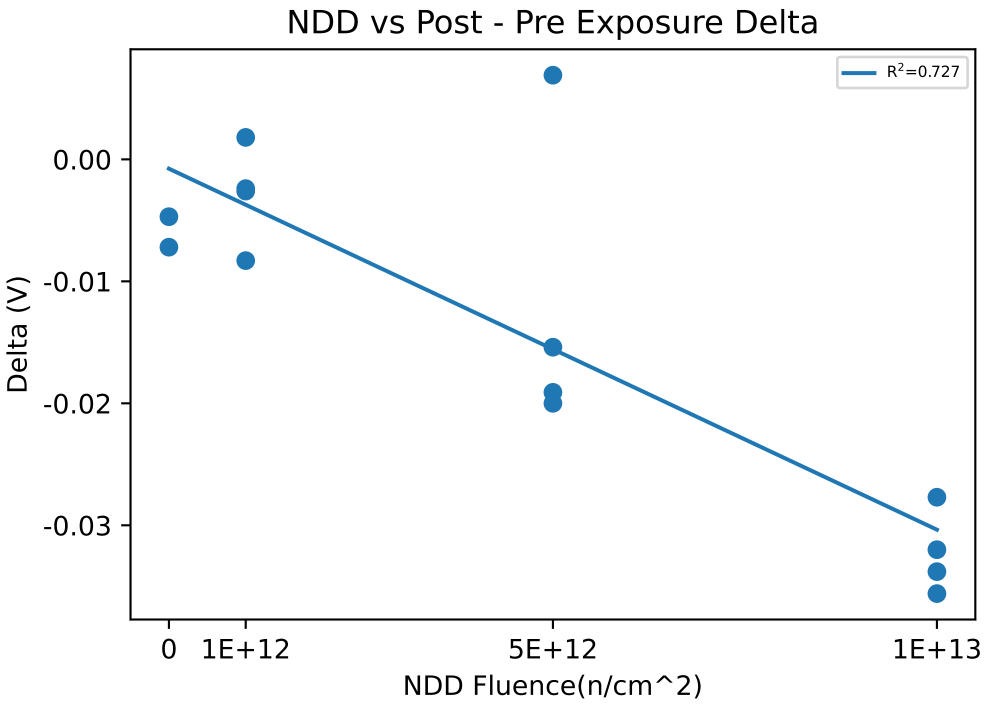
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	5.0232	4.9949	-0.0283
2	0	Correlation	5.0227	5.0245	0.0018
30	1e+12	NDD unbiased	5.0273	5.0054	-0.0219
31	1e+12	NDD unbiased	5.0084	5.0239	0.0155
32	1e+12	NDD unbiased	5.0082	5.0047	-0.0035
33	1e+12	NDD unbiased	4.9962	4.9928	-0.0034
44	5e+12	NDD unbiased	4.9988	4.9819	-0.0169
45	5e+12	NDD unbiased	5.0229	4.9893	-0.0336
46	5e+12	NDD unbiased	5.0072	4.9887	-0.0185
47	5e+12	NDD unbiased	5.0088	4.9892	-0.0196
50	1e+13	NDD unbiased	4.9928	4.9607	-0.0321
51	1e+13	NDD unbiased	5.0049	4.9725	-0.0324
52	1e+13	NDD unbiased	5.0209	4.9899	-0.031
53	1e+13	NDD unbiased	4.9997	4.9667	-0.033

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.0227	5.0229	5.0232	0.00035355	4.9949	5.0097	5.0245	0.02093	-0.0283	-0.01325	0.0018	0.021284
1e+12	4.9962	5.01	5.0273	0.012852	4.9928	5.0067	5.0239	0.012842	-0.0219	-0.003325	0.0155	0.015269
5e+12	4.9988	5.0094	5.0229	0.0099968	4.9819	4.9873	4.9893	0.0035929	-0.0336	-0.02215	-0.0169	0.0077134
1e+13	4.9928	5.0046	5.0209	0.011959	4.9607	4.9725	4.9899	0.012591	-0.033	-0.032125	-0.031	0.00083815

Device Test: 60.11 V_BP5H(_V_BP5H PWM 5MHz VIN_10V)





Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

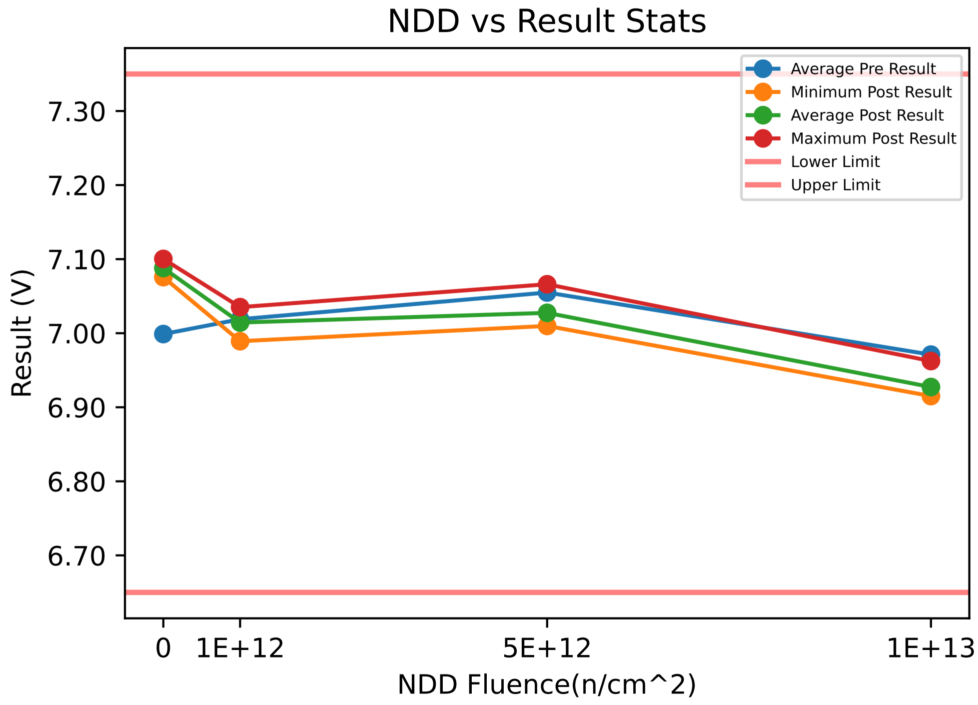
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	5.0021	4.9974	-0.0047
2	0	Correlation	5.0324	5.0252	-0.0072
30	1e+12	NDD unbiased	4.9952	4.997	0.0018
31	1e+12	NDD unbiased	5.0018	4.9935	-0.0083
32	1e+12	NDD unbiased	5.0141	5.0115	-0.0026
33	1e+12	NDD unbiased	5.017	5.0146	-0.0024
44	5e+12	NDD unbiased	5.01	4.9909	-0.0191
45	5e+12	NDD unbiased	4.9971	5.004	0.0069
46	5e+12	NDD unbiased	4.9971	4.9771	-0.02
47	5e+12	NDD unbiased	5.0193	5.0039	-0.0154
50	1e+13	NDD unbiased	5.0233	4.9913	-0.032
51	1e+13	NDD unbiased	4.9944	4.9606	-0.0338
52	1e+13	NDD unbiased	5.008	4.9803	-0.0277
53	1e+13	NDD unbiased	5.002	4.9664	-0.0356

Test Statistics (V)

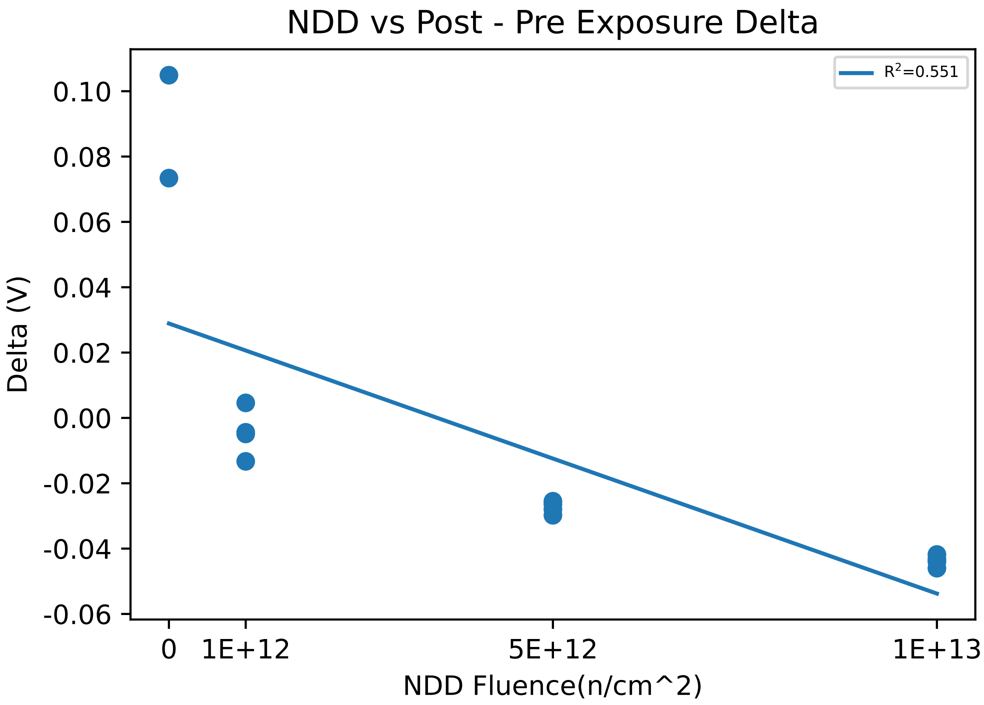
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.0021	5.0173	5.0324	0.021425	4.9974	5.0113	5.0252	0.019658	-0.0072	-0.00595	-0.0047	0.0017678
1e+12	4.9952	5.007	5.017	0.010274	4.9935	5.0042	5.0146	0.010453	-0.0083	-0.002875	0.0018	0.0041468
5e+12	4.9971	5.0059	5.0193	0.01082	4.9771	4.994	5.004	0.012822	-0.02	-0.0119	0.0069	0.01269
1e+13	4.9944	5.0069	5.0233	0.012253	4.9606	4.9747	4.9913	0.01384	-0.0356	-0.032275	-0.0277	0.0033856

Device Test: 60.12 V_BP7L(_V_BP7L IIM 500kHz VIN_10V)

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



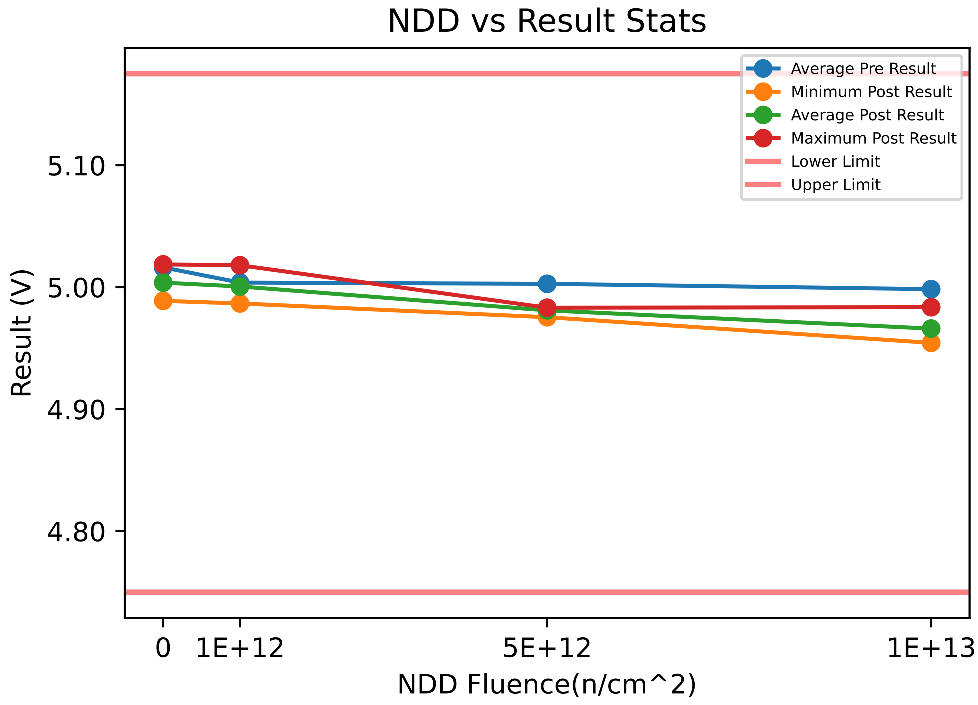
Test Results (Lower Limit = 6.65, Upper Limit = 7.35 (V))

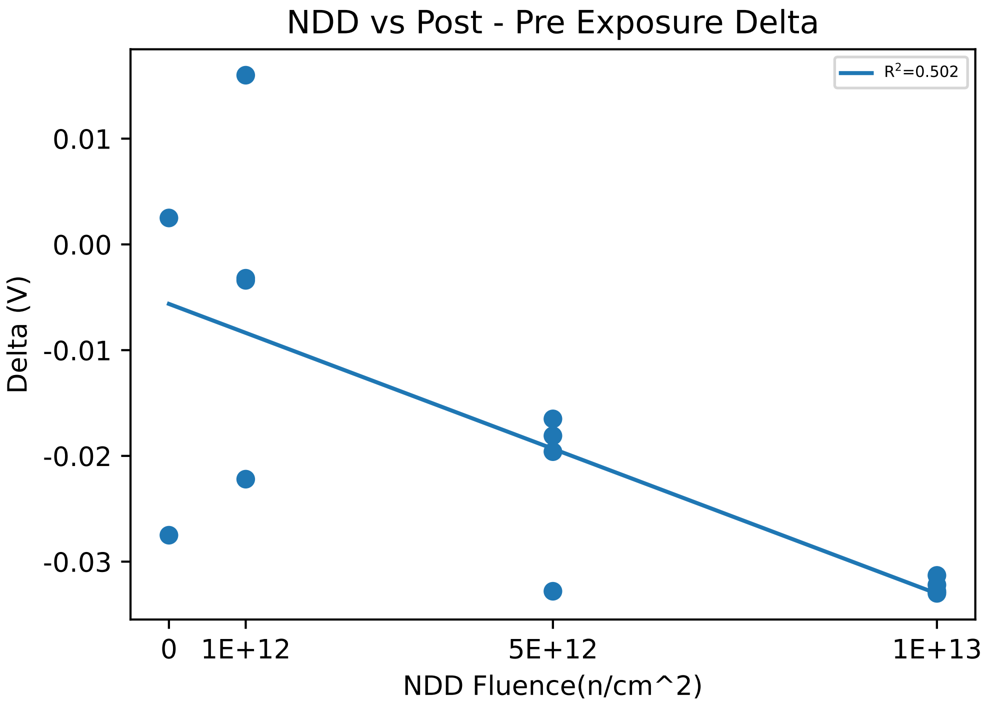
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	7.0023	7.0757	0.0734
2	0	Correlation	6.9954	7.1003	0.1049
30	1e+12	NDD unbiased	7.0306	7.0352	0.0046
31	1e+12	NDD unbiased	7.0396	7.0263	-0.0133
32	1e+12	NDD unbiased	6.9941	6.9892	-0.0049
33	1e+12	NDD unbiased	7.0112	7.0068	-0.0044
44	5e+12	NDD unbiased	7.0496	7.0241	-0.0255
45	5e+12	NDD unbiased	7.0397	7.0099	-0.0298
46	5e+12	NDD unbiased	7.0926	7.0661	-0.0265
47	5e+12	NDD unbiased	7.0378	7.0098	-0.028
50	1e+13	NDD unbiased	6.9575	6.9157	-0.0418
51	1e+13	NDD unbiased	6.9591	6.9151	-0.044
52	1e+13	NDD unbiased	6.9593	6.9161	-0.0432
53	1e+13	NDD unbiased	7.0084	6.9624	-0.046

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	6.9954	6.9989	7.0023	0.004879	7.0757	7.088	7.1003	0.017395	0.0734	0.08915	0.1049	0.022274
1e+12	6.9941	7.0189	7.0396	0.020328	6.9892	7.0144	7.0352	0.020551	-0.0133	-0.0045	0.0046	0.0073125
5e+12	7.0378	7.0549	7.0926	0.025644	7.0098	7.0275	7.0661	0.026612	-0.0298	-0.02745	-0.0255	0.0018735
1e+13	6.9575	6.9711	7.0084	0.024896	6.9151	6.9273	6.9624	0.023387	-0.046	-0.04375	-0.0418	0.001754

Device Test: 60.13 V_BP5L(_V_BP5L IIM 500kHz VIN_10V)


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

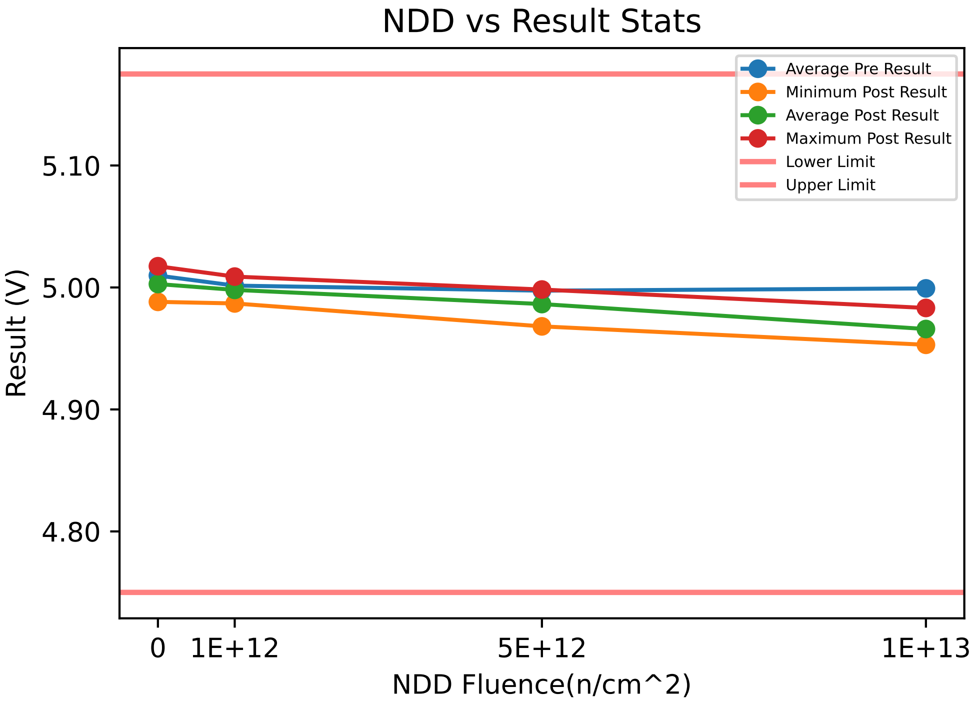
Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

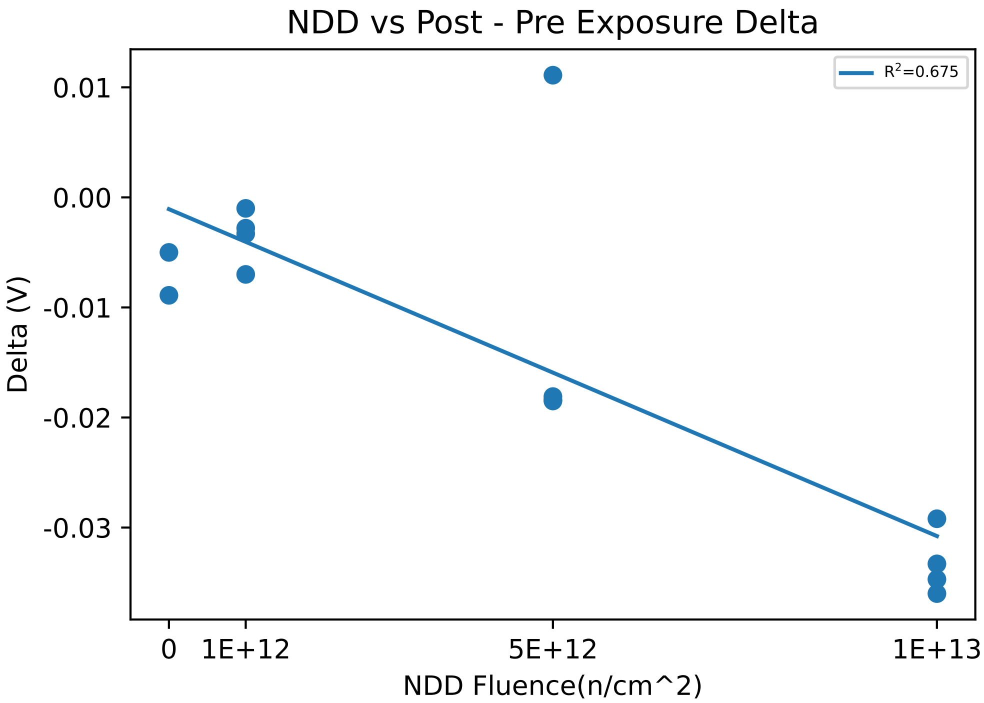
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	5.0163	4.9888	-0.0275
2	0	Correlation	5.0162	5.0187	0.0025
30	1e+12	NDD unbiased	5.0214	4.9992	-0.0222
31	1e+12	NDD unbiased	5.002	5.018	0.016
32	1e+12	NDD unbiased	5.0019	4.9985	-0.0034
33	1e+12	NDD unbiased	4.9899	4.9867	-0.0032
44	5e+12	NDD unbiased	4.9919	4.9754	-0.0165
45	5e+12	NDD unbiased	5.016	4.9832	-0.0328
46	5e+12	NDD unbiased	5.0005	4.9824	-0.0181
47	5e+12	NDD unbiased	5.0027	4.9831	-0.0196
50	1e+13	NDD unbiased	4.9866	4.9544	-0.0322
51	1e+13	NDD unbiased	4.9986	4.9658	-0.0328
52	1e+13	NDD unbiased	5.0149	4.9836	-0.0313
53	1e+13	NDD unbiased	4.9935	4.9605	-0.033

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.0162	5.0163	5.0163	7.0711e-05	4.9888	5.0038	5.0187	0.021142	-0.0275	-0.0125	0.0025	0.021213
1e+12	4.9899	5.0038	5.0214	0.013036	4.9867	5.0006	5.018	0.01294	-0.0222	-0.0032	0.016	0.015596
5e+12	4.9919	5.0028	5.016	0.0099724	4.9754	4.981	4.9832	0.0037669	-0.0328	-0.02175	-0.0165	0.0074746
1e+13	4.9866	4.9984	5.0149	0.012049	4.9544	4.9661	4.9836	0.012578	-0.033	-0.032325	-0.0313	0.00076322

Device Test: 60.14 V_BP5H(_V_BP5H IIM 500kHz VIN_10V)


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

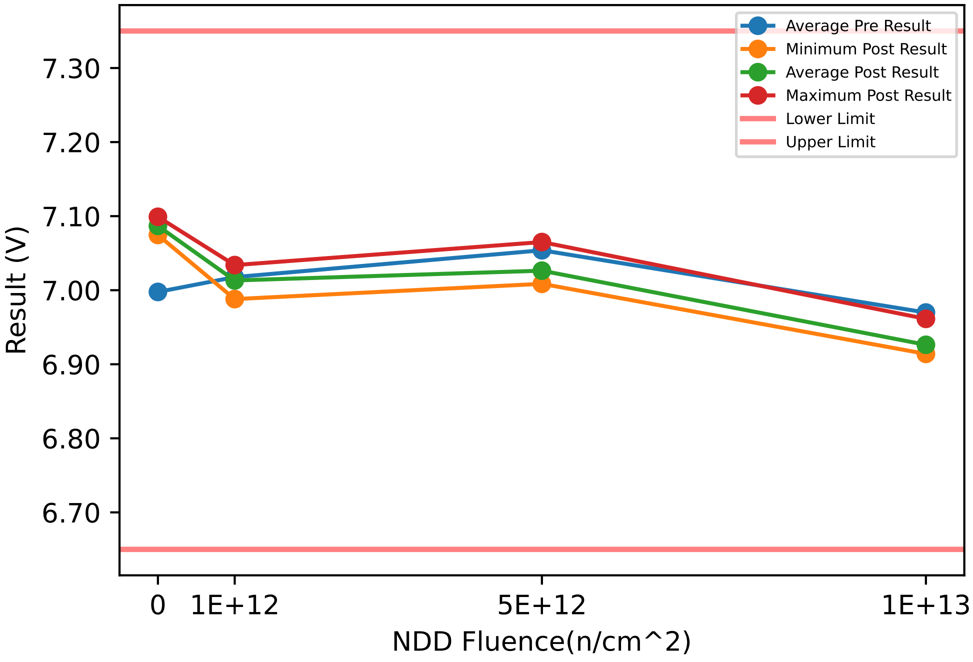
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	4.9971	4.9882	-0.0089
2	0	Correlation	5.0224	5.0174	-0.005
30	1e+12	NDD unbiased	4.9903	4.9893	-0.001
31	1e+12	NDD unbiased	4.9939	4.9869	-0.007
32	1e+12	NDD unbiased	5.0122	5.0089	-0.0033
33	1e+12	NDD unbiased	5.0097	5.0069	-0.0028
44	5e+12	NDD unbiased	4.9994	4.9813	-0.0181
45	5e+12	NDD unbiased	4.9872	4.9983	0.0111
46	5e+12	NDD unbiased	4.9866	4.9681	-0.0185
47	5e+12	NDD unbiased	5.0163	4.9979	-0.0184
50	1e+13	NDD unbiased	5.0165	4.9832	-0.0333
51	1e+13	NDD unbiased	4.989	4.953	-0.036
52	1e+13	NDD unbiased	5.0004	4.9712	-0.0292
53	1e+13	NDD unbiased	4.991	4.9563	-0.0347

Test Statistics (V)

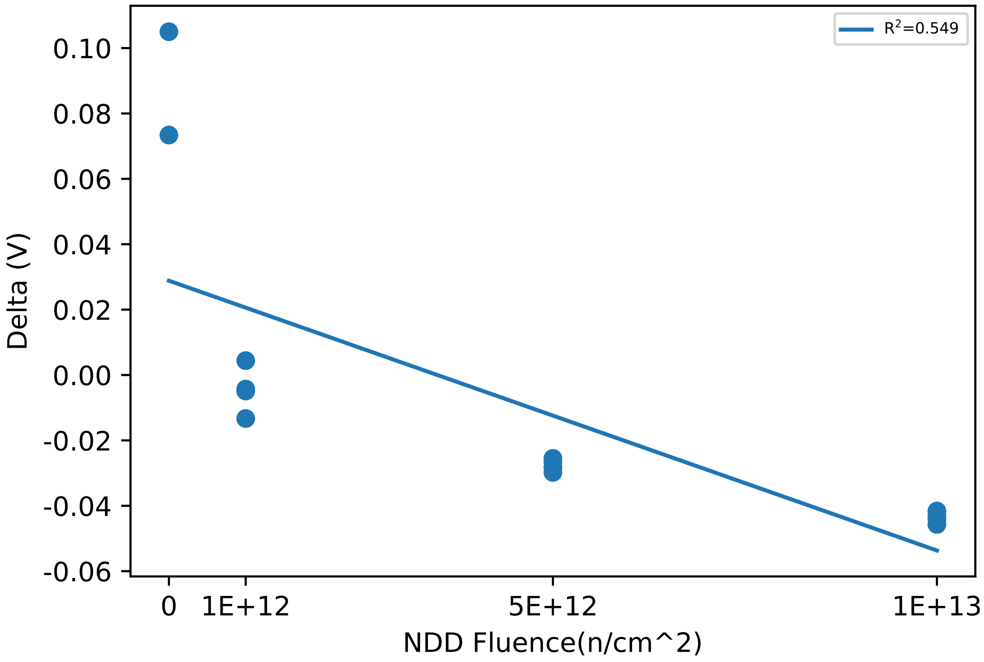
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.9971	5.0098	5.0224	0.01789	4.9882	5.0028	5.0174	0.020648	-0.0089	-0.00695	-0.005	0.0027577
1e+12	4.9903	5.0015	5.0122	0.011029	4.9869	4.998	5.0089	0.011502	-0.007	-0.003525	-0.001	0.0025184
5e+12	4.9866	4.9974	5.0163	0.013927	4.9681	4.9864	4.9983	0.014546	-0.0185	-0.010975	0.0111	0.014718
1e+13	4.989	4.9992	5.0165	0.012543	4.953	4.9659	4.9832	0.013976	-0.036	-0.0333	-0.0292	0.0029473

Device Test: 60.15 V_BP7L(_V_BP7L IIM 1MHz VIN_10V)

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



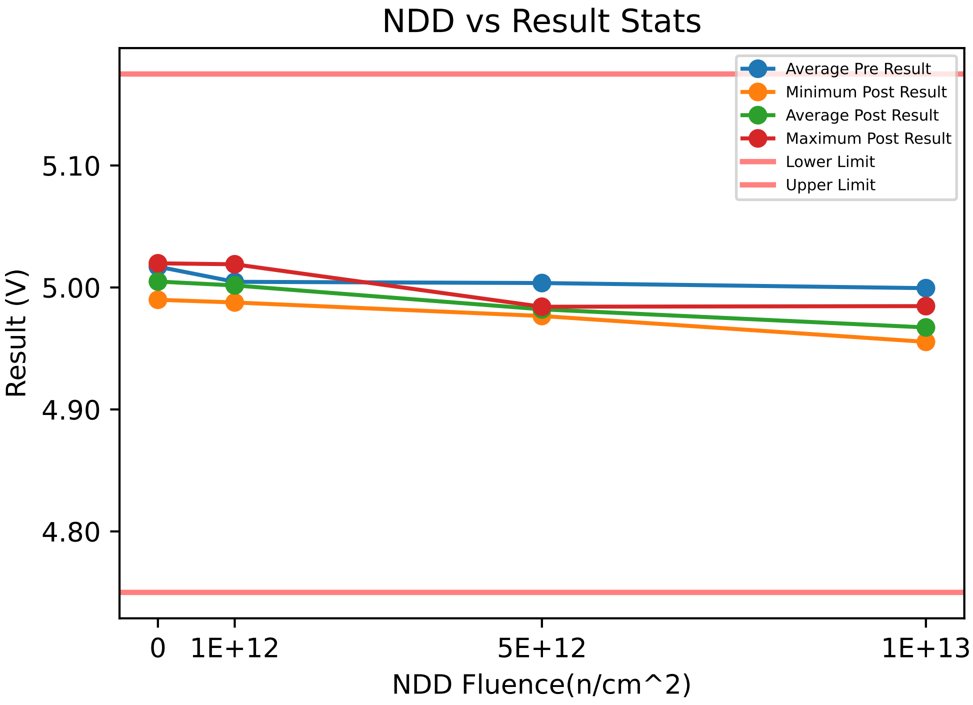
Test Results (Lower Limit = 6.65, Upper Limit = 7.35 (V))

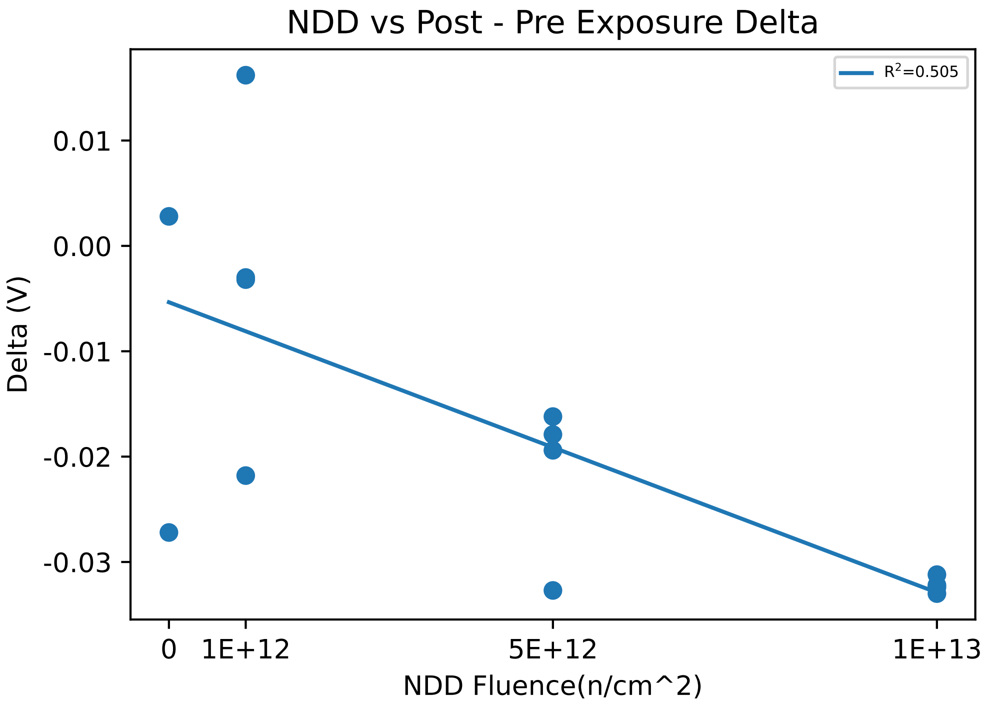
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	7.0012	7.0746	0.0734
2	0	Correlation	6.9941	7.0991	0.105
30	1e+12	NDD unbiased	7.0295	7.0339	0.0044
31	1e+12	NDD unbiased	7.0384	7.0251	-0.0133
32	1e+12	NDD unbiased	6.9929	6.988	-0.0049
33	1e+12	NDD unbiased	7.0099	7.0056	-0.0043
44	5e+12	NDD unbiased	7.0485	7.023	-0.0255
45	5e+12	NDD unbiased	7.0386	7.0088	-0.0298
46	5e+12	NDD unbiased	7.0916	7.065	-0.0266
47	5e+12	NDD unbiased	7.0369	7.0086	-0.0283
50	1e+13	NDD unbiased	6.9562	6.9146	-0.0416
51	1e+13	NDD unbiased	6.9581	6.914	-0.0441
52	1e+13	NDD unbiased	6.9581	6.9151	-0.043
53	1e+13	NDD unbiased	7.007	6.9613	-0.0457

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	6.9941	6.9977	7.0012	0.0050205	7.0746	7.0869	7.0991	0.017324	0.0734	0.0892	0.105	0.022345
1e+12	6.9929	7.0177	7.0384	0.02036	6.988	7.0132	7.0339	0.020517	-0.0133	-0.004525	0.0044	0.0072307
5e+12	7.0369	7.0539	7.0916	0.025649	7.0086	7.0263	7.065	0.026634	-0.0298	-0.02755	-0.0255	0.0018912
1e+13	6.9562	6.9699	7.007	0.024783	6.914	6.9262	6.9613	0.023371	-0.0457	-0.0436	-0.0416	0.001734

Device Test: 60.16 V_BP5L(_V_BP5L IIM 1MHz VIN_10V)





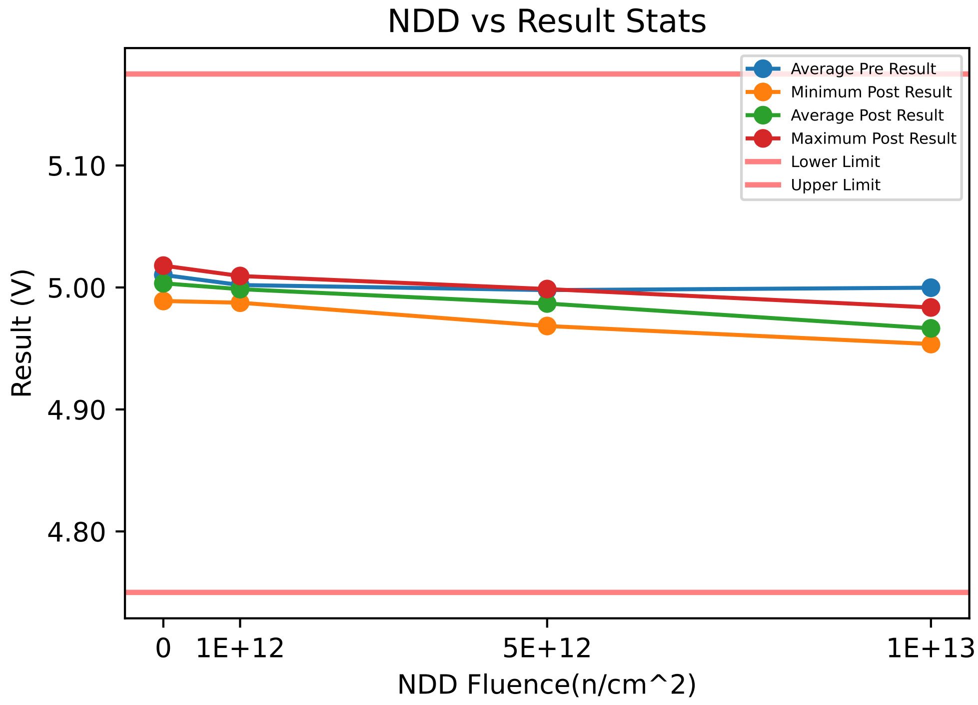
Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

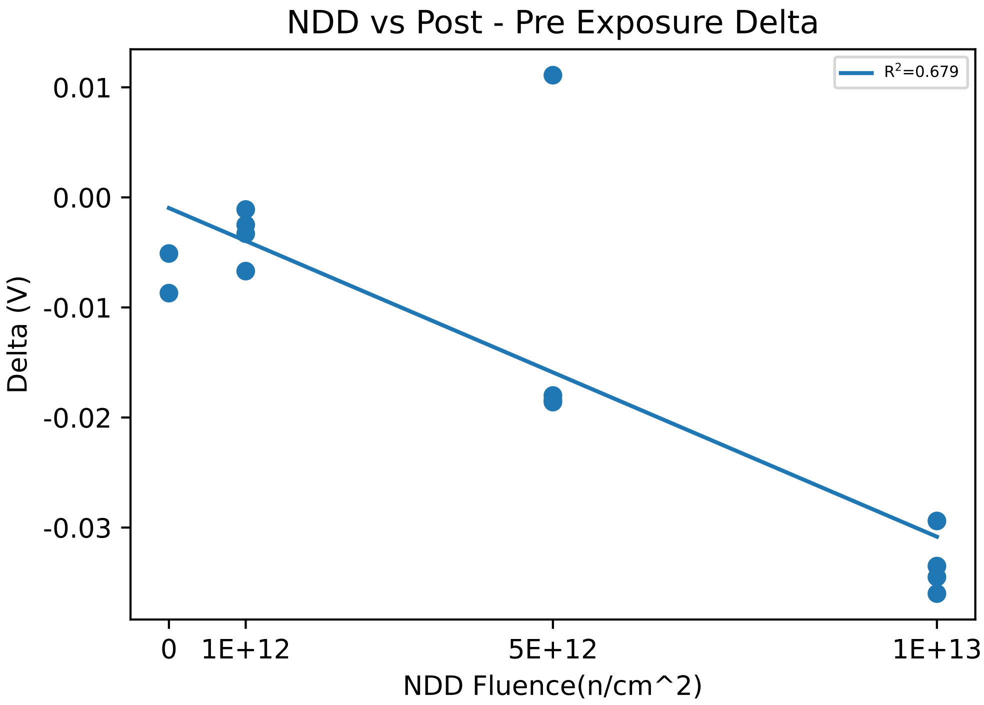
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	5.0171	4.9899	-0.0272
2	0	Correlation	5.017	5.0198	0.0028
30	1e+12	NDD unbiased	5.0222	5.0004	-0.0218
31	1e+12	NDD unbiased	5.0028	5.019	0.0162
32	1e+12	NDD unbiased	5.0026	4.9996	-0.003
33	1e+12	NDD unbiased	4.9909	4.9877	-0.0032
44	5e+12	NDD unbiased	4.9928	4.9766	-0.0162
45	5e+12	NDD unbiased	5.0169	4.9842	-0.0327
46	5e+12	NDD unbiased	5.0013	4.9834	-0.0179
47	5e+12	NDD unbiased	5.0035	4.9841	-0.0194
50	1e+13	NDD unbiased	4.9876	4.9554	-0.0322
51	1e+13	NDD unbiased	4.9996	4.9672	-0.0324
52	1e+13	NDD unbiased	5.0159	4.9847	-0.0312
53	1e+13	NDD unbiased	4.9946	4.9616	-0.033

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.017	5.0171	5.0171	7.0711e-05	4.9899	5.0048	5.0198	0.021142	-0.0272	-0.0122	0.0028	0.021213
1e+12	4.9909	5.0046	5.0222	0.01297	4.9877	5.0017	5.019	0.012928	-0.0218	-0.00295	0.0162	0.015515
5e+12	4.9928	5.0036	5.0169	0.0099804	4.9766	4.9821	4.9842	0.0036673	-0.0327	-0.02155	-0.0162	0.0075474
1e+13	4.9876	4.9994	5.0159	0.012036	4.9554	4.9672	4.9847	0.012608	-0.033	-0.0322	-0.0312	0.00074833

Device Test: 60.17 V_BP5H(_V_BP5H IIM 1MHz VIN_10V)





Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

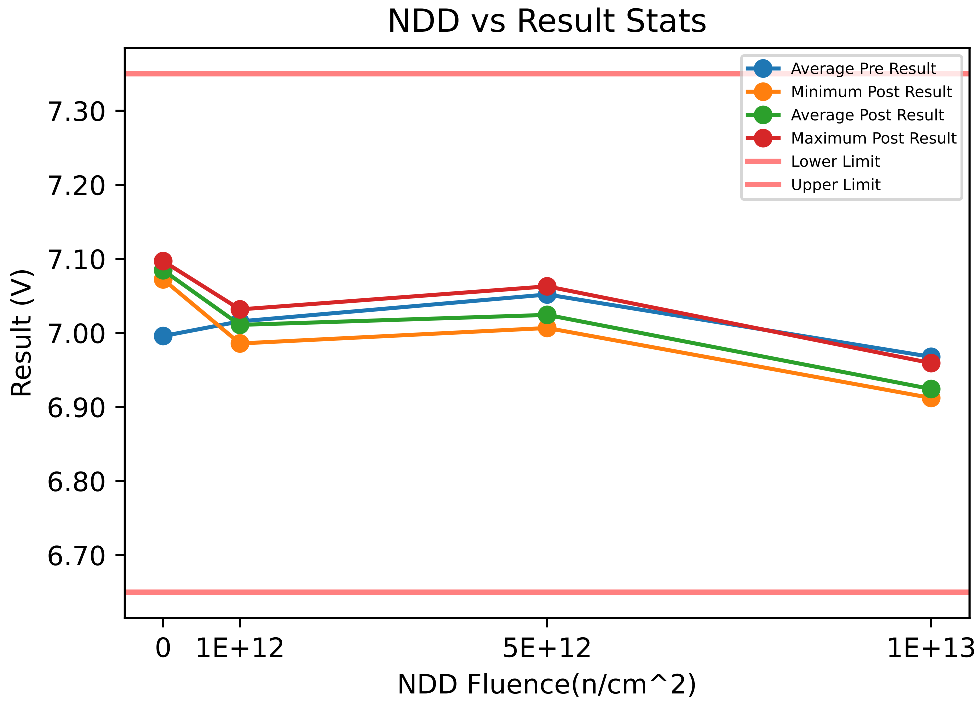
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	4.9976	4.9889	-0.0087
2	0	Correlation	5.023	5.0179	-0.0051
30	1e+12	NDD unbiased	4.991	4.9899	-0.0011
31	1e+12	NDD unbiased	4.9942	4.9875	-0.0067
32	1e+12	NDD unbiased	5.0127	5.0094	-0.0033
33	1e+12	NDD unbiased	5.0101	5.0076	-0.0025
44	5e+12	NDD unbiased	4.9999	4.9819	-0.018
45	5e+12	NDD unbiased	4.9876	4.9987	0.0111
46	5e+12	NDD unbiased	4.987	4.9684	-0.0186
47	5e+12	NDD unbiased	5.0168	4.9984	-0.0184
50	1e+13	NDD unbiased	5.0171	4.9836	-0.0335
51	1e+13	NDD unbiased	4.9896	4.9536	-0.036
52	1e+13	NDD unbiased	5.001	4.9716	-0.0294
53	1e+13	NDD unbiased	4.9915	4.957	-0.0345

Test Statistics (V)

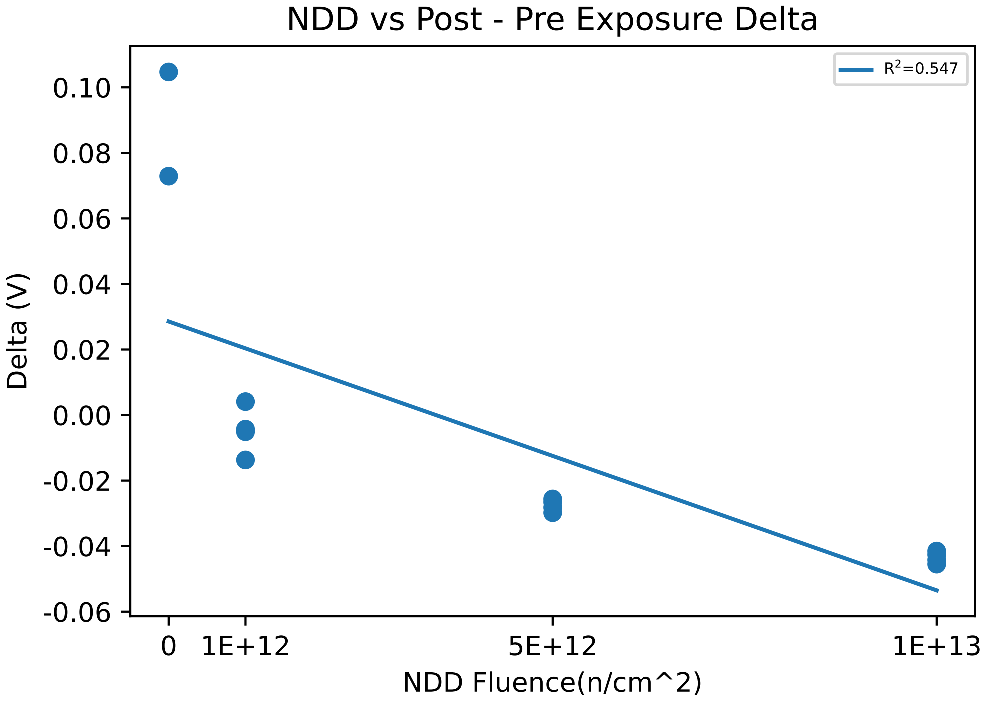
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.9976	5.0103	5.023	0.017961	4.9889	5.0034	5.0179	0.020506	-0.0087	-0.0069	-0.0051	0.0025456
1e+12	4.991	5.002	5.0127	0.010984	4.9875	4.9986	5.0094	0.011497	-0.0067	-0.0034	-0.0011	0.0023805
5e+12	4.987	4.9978	5.0168	0.013977	4.9684	4.9869	4.9987	0.014591	-0.0186	-0.010975	0.0111	0.014719
1e+13	4.9896	4.9998	5.0171	0.012565	4.9536	4.9665	4.9836	0.013845	-0.036	-0.03335	-0.0294	0.0028267

Device Test: 60.18 V_BP7L(_V_BP7L IIM 2MHz VIN_10V)

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



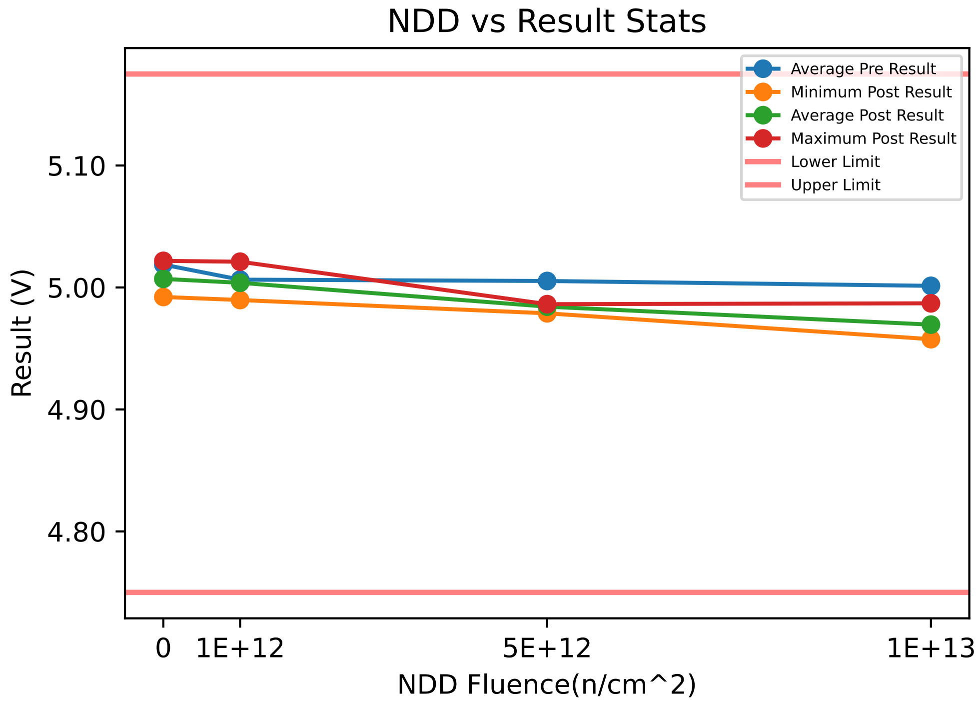
Test Results (Lower Limit = 6.65, Upper Limit = 7.35 (V))

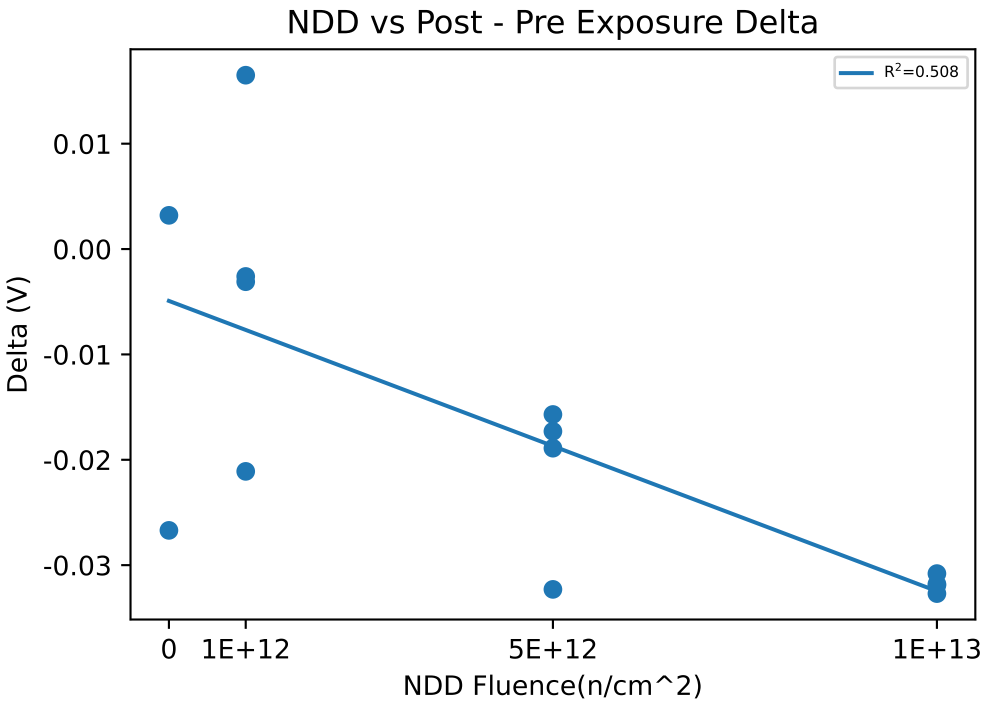
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	6.9994	7.0723	0.0729
2	0	Correlation	6.9923	7.097	0.1047
30	1e+12	NDD unbiased	7.0277	7.0318	0.0041
31	1e+12	NDD unbiased	7.0365	7.0228	-0.0137
32	1e+12	NDD unbiased	6.9909	6.9858	-0.0051
33	1e+12	NDD unbiased	7.0074	7.0031	-0.0043
44	5e+12	NDD unbiased	7.0466	7.021	-0.0256
45	5e+12	NDD unbiased	7.0367	7.0069	-0.0298
46	5e+12	NDD unbiased	7.0895	7.0629	-0.0266
47	5e+12	NDD unbiased	7.0349	7.0067	-0.0282
50	1e+13	NDD unbiased	6.954	6.9125	-0.0415
51	1e+13	NDD unbiased	6.9564	6.9122	-0.0442
52	1e+13	NDD unbiased	6.9558	6.9132	-0.0426
53	1e+13	NDD unbiased	7.0048	6.9593	-0.0455

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	6.9923	6.9958	6.9994	0.0050205	7.0723	7.0846	7.097	0.017466	0.0729	0.0888	0.1047	0.022486
1e+12	6.9909	7.0156	7.0365	0.020498	6.9858	7.0109	7.0318	0.020569	-0.0137	-0.00475	0.0041	0.0072744
5e+12	7.0349	7.0519	7.0895	0.025573	7.0067	7.0244	7.0629	0.026541	-0.0298	-0.02755	-0.0256	0.001843
1e+13	6.954	6.9678	7.0048	0.024721	6.9122	6.9243	6.9593	0.023337	-0.0455	-0.04345	-0.0415	0.0017597

Device Test: 60.19 V_BP5L(_V_BP5L IIM 2MHz VIN_10V)





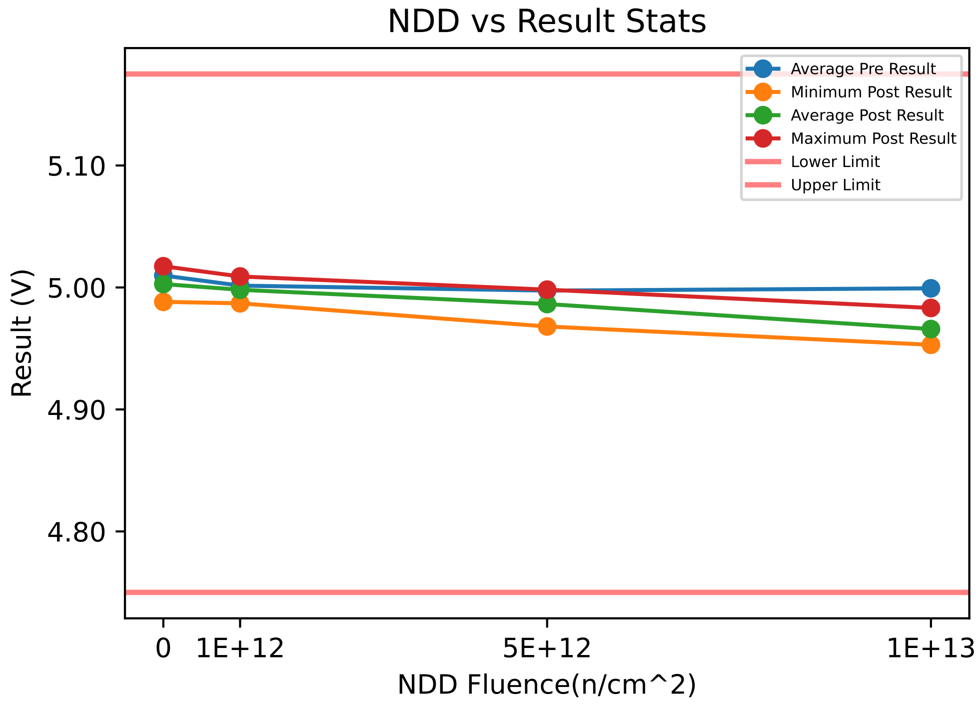
Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

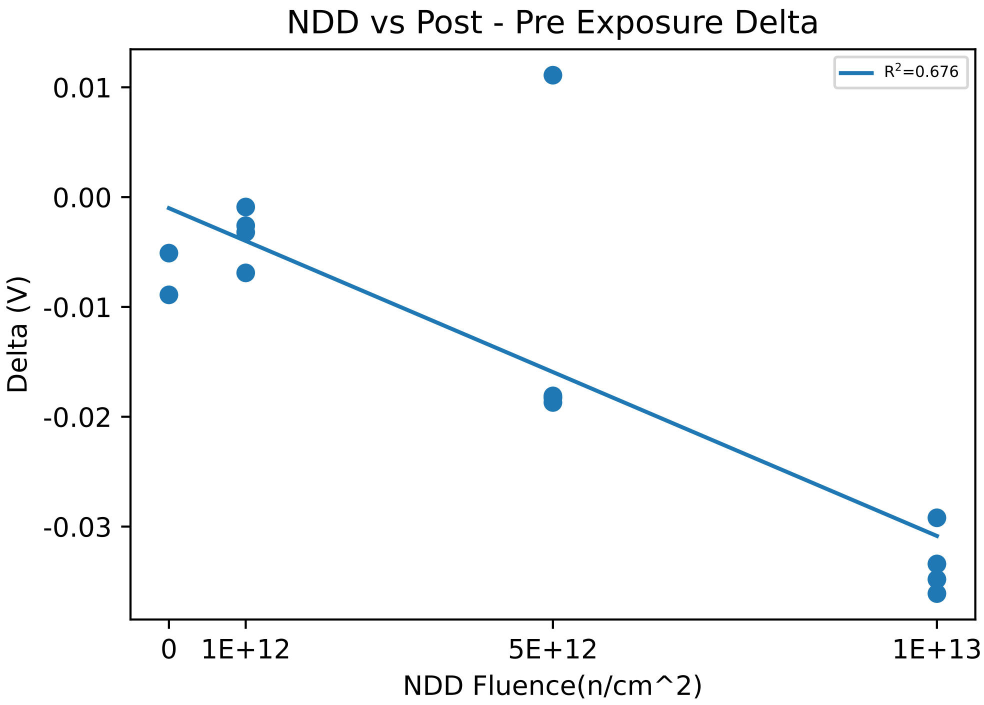
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	5.0189	4.9922	-0.0267
2	0	Correlation	5.0186	5.0218	0.0032
30	1e+12	NDD unbiased	5.0239	5.0028	-0.0211
31	1e+12	NDD unbiased	5.0046	5.0211	0.0165
32	1e+12	NDD unbiased	5.0043	5.0017	-0.0026
33	1e+12	NDD unbiased	4.9928	4.9897	-0.0031
44	5e+12	NDD unbiased	4.9945	4.9788	-0.0157
45	5e+12	NDD unbiased	5.0186	4.9863	-0.0323
46	5e+12	NDD unbiased	5.003	4.9857	-0.0173
47	5e+12	NDD unbiased	5.0051	4.9862	-0.0189
50	1e+13	NDD unbiased	4.9895	4.9576	-0.0319
51	1e+13	NDD unbiased	5.0015	4.9697	-0.0318
52	1e+13	NDD unbiased	5.0178	4.987	-0.0308
53	1e+13	NDD unbiased	4.9965	4.9638	-0.0327

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.0186	5.0188	5.0189	0.00021213	4.9922	5.007	5.0218	0.02093	-0.0267	-0.01175	0.0032	0.021142
1e+12	4.9928	5.0064	5.0239	0.012895	4.9897	5.0038	5.0211	0.012955	-0.0211	-0.002575	0.0165	0.015355
5e+12	4.9945	5.0053	5.0186	0.009981	4.9788	4.9842	4.9863	0.0036428	-0.0323	-0.02105	-0.0157	0.0076129
1e+13	4.9895	5.0013	5.0178	0.012036	4.9576	4.9695	4.987	0.012654	-0.0327	-0.0318	-0.0308	0.00077889

Device Test: 60.2 V_BP5H(_V_BP5H PWM 500kHz VIN_10V)





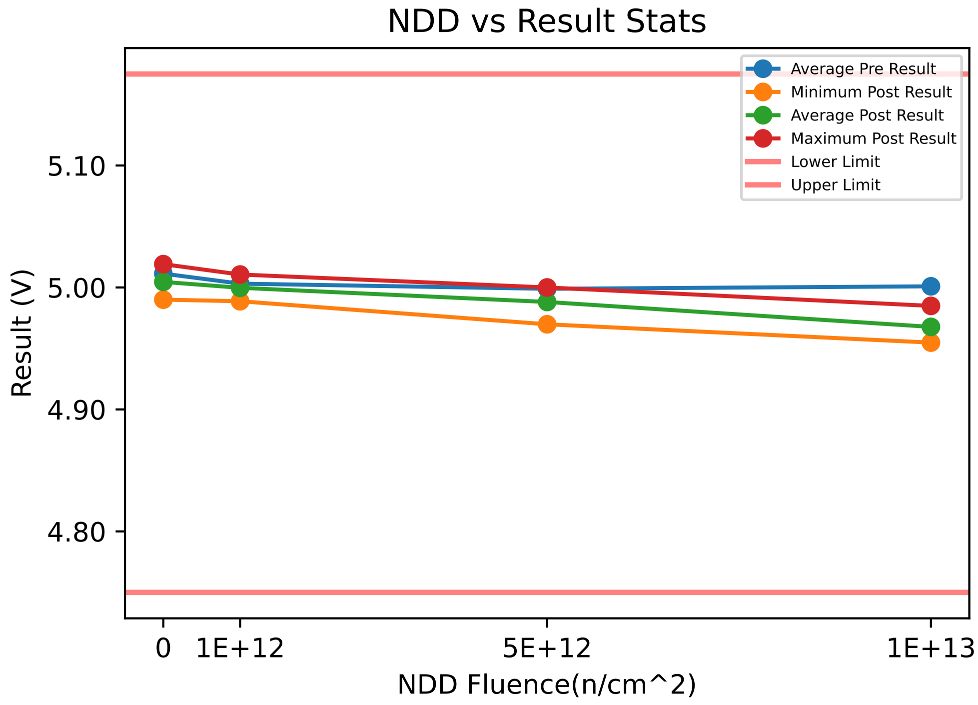
Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

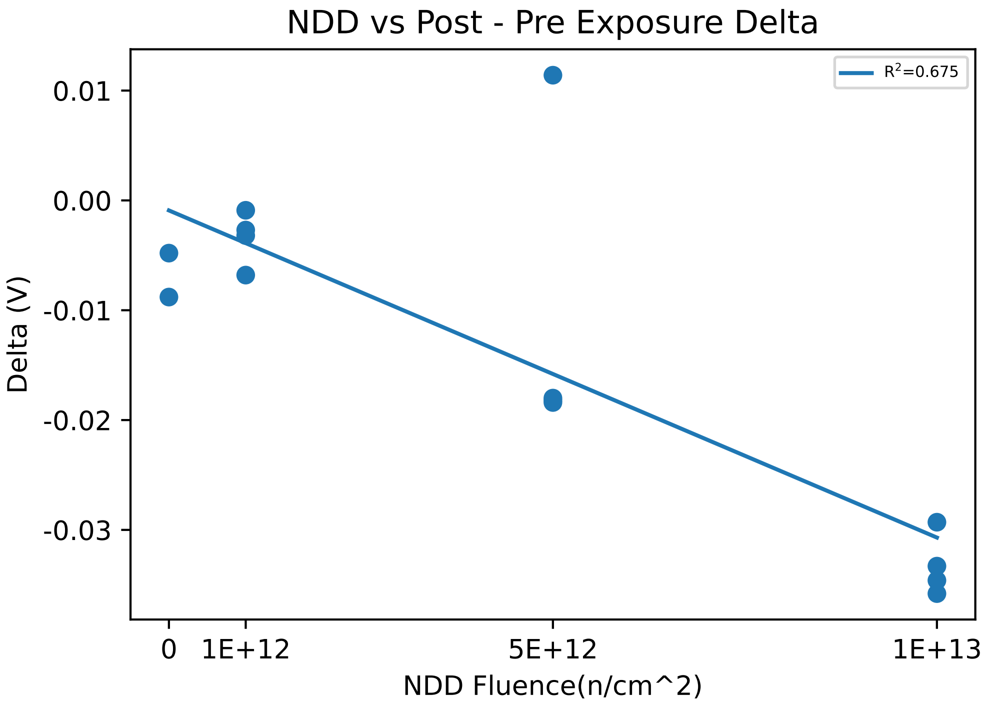
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	4.9971	4.9882	-0.0089
2	0	Correlation	5.0225	5.0174	-0.0051
30	1e+12	NDD unbiased	4.9903	4.9894	-0.0009
31	1e+12	NDD unbiased	4.9939	4.987	-0.0069
32	1e+12	NDD unbiased	5.0122	5.009	-0.0032
33	1e+12	NDD unbiased	5.0096	5.007	-0.0026
44	5e+12	NDD unbiased	4.9995	4.9814	-0.0181
45	5e+12	NDD unbiased	4.9871	4.9982	0.0111
46	5e+12	NDD unbiased	4.9867	4.968	-0.0187
47	5e+12	NDD unbiased	5.0164	4.9981	-0.0183
50	1e+13	NDD unbiased	5.0166	4.9832	-0.0334
51	1e+13	NDD unbiased	4.9891	4.953	-0.0361
52	1e+13	NDD unbiased	5.0004	4.9712	-0.0292
53	1e+13	NDD unbiased	4.991	4.9562	-0.0348

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.9971	5.0098	5.0225	0.017961	4.9882	5.0028	5.0174	0.020648	-0.0089	-0.007	-0.0051	0.002687
1e+12	4.9903	5.0015	5.0122	0.011005	4.987	4.9981	5.009	0.011502	-0.0069	-0.0034	-0.0009	0.0025285
5e+12	4.9867	4.9974	5.0164	0.013976	4.968	4.9864	4.9982	0.014602	-0.0187	-0.011	0.0111	0.014735
1e+13	4.9891	4.9993	5.0166	0.012562	4.953	4.9659	4.9832	0.013999	-0.0361	-0.033375	-0.0292	0.0029937

Device Test: 60.20 V_BP5H(_V_BP5H IIM 2MHz VIN_10V)





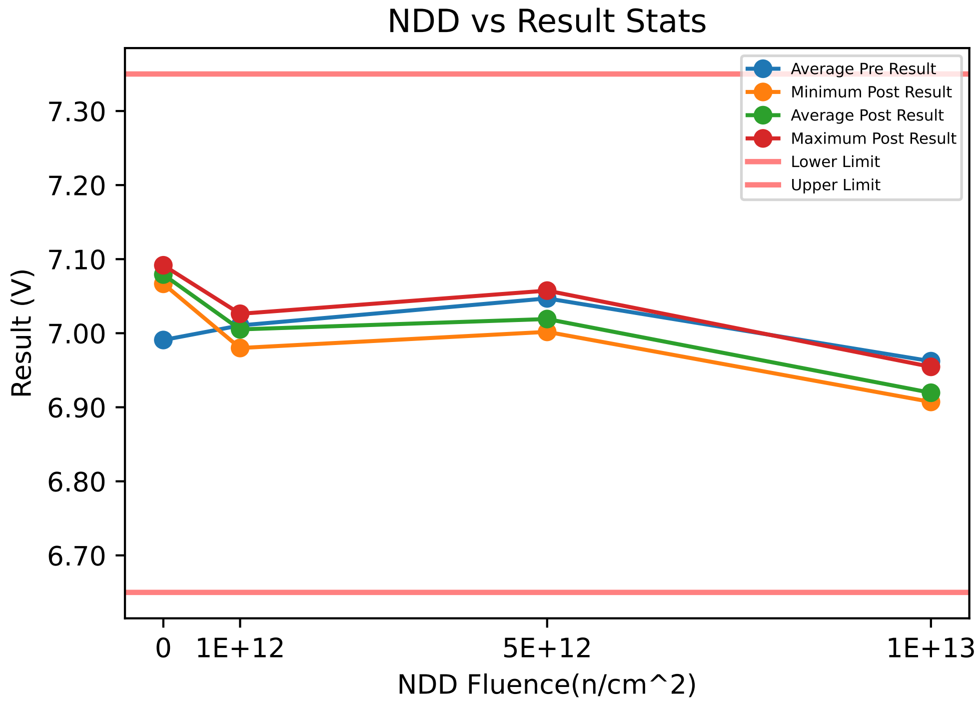
Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

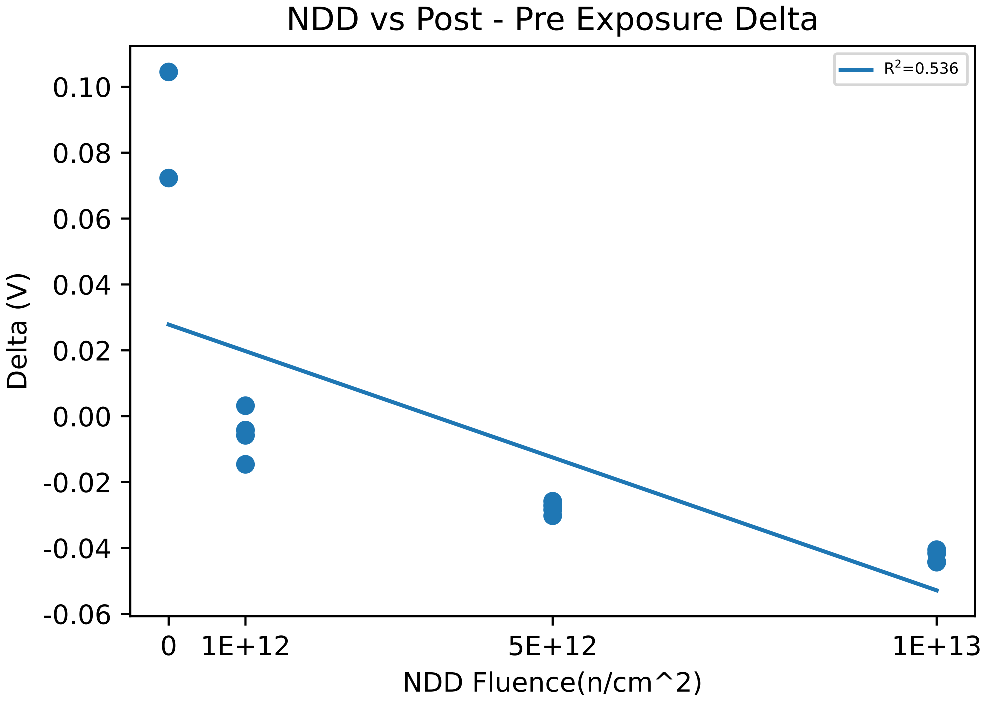
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	4.9988	4.99	-0.0088
2	0	Correlation	5.0239	5.0191	-0.0048
30	1e+12	NDD unbiased	4.9919	4.991	-0.0009
31	1e+12	NDD unbiased	4.9955	4.9887	-0.0068
32	1e+12	NDD unbiased	5.0138	5.0106	-0.0032
33	1e+12	NDD unbiased	5.0113	5.0086	-0.0027
44	5e+12	NDD unbiased	5.001	4.983	-0.018
45	5e+12	NDD unbiased	4.9886	5	0.0114
46	5e+12	NDD unbiased	4.9882	4.9698	-0.0184
47	5e+12	NDD unbiased	5.0178	4.9996	-0.0182
50	1e+13	NDD unbiased	5.0182	4.9849	-0.0333
51	1e+13	NDD unbiased	4.9906	4.9548	-0.0358
52	1e+13	NDD unbiased	5.0021	4.9728	-0.0293
53	1e+13	NDD unbiased	4.9928	4.9582	-0.0346

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.9988	5.0114	5.0239	0.017748	4.99	5.0046	5.0191	0.020577	-0.0088	-0.0068	-0.0048	0.0028284
1e+12	4.9919	5.0031	5.0138	0.011029	4.9887	4.9997	5.0106	0.01147	-0.0068	-0.0034	-0.0009	0.0024725
5e+12	4.9882	4.9989	5.0178	0.013931	4.9698	4.9881	5	0.014546	-0.0184	-0.0108	0.0114	0.014801
1e+13	4.9906	5.0009	5.0182	0.012549	4.9548	4.9677	4.9849	0.013887	-0.0358	-0.03325	-0.0293	0.0028243

Device Test: 60.21 V_BP7L(_V_BP7L IIM 5MHz VIN_10V)





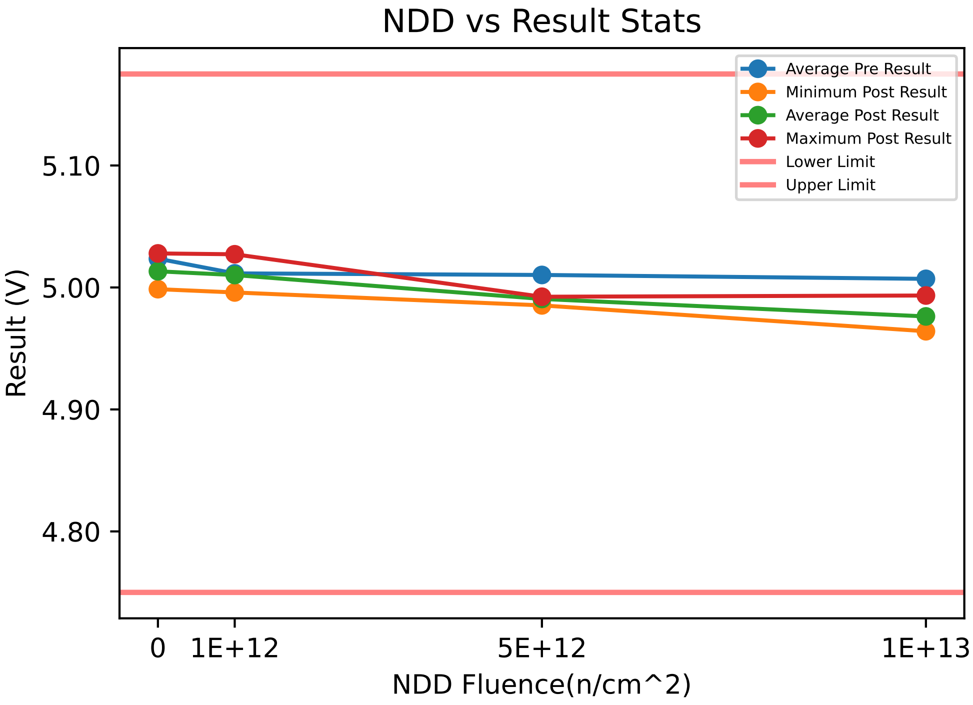
Test Results (Lower Limit = 6.65, Upper Limit = 7.35 (V))

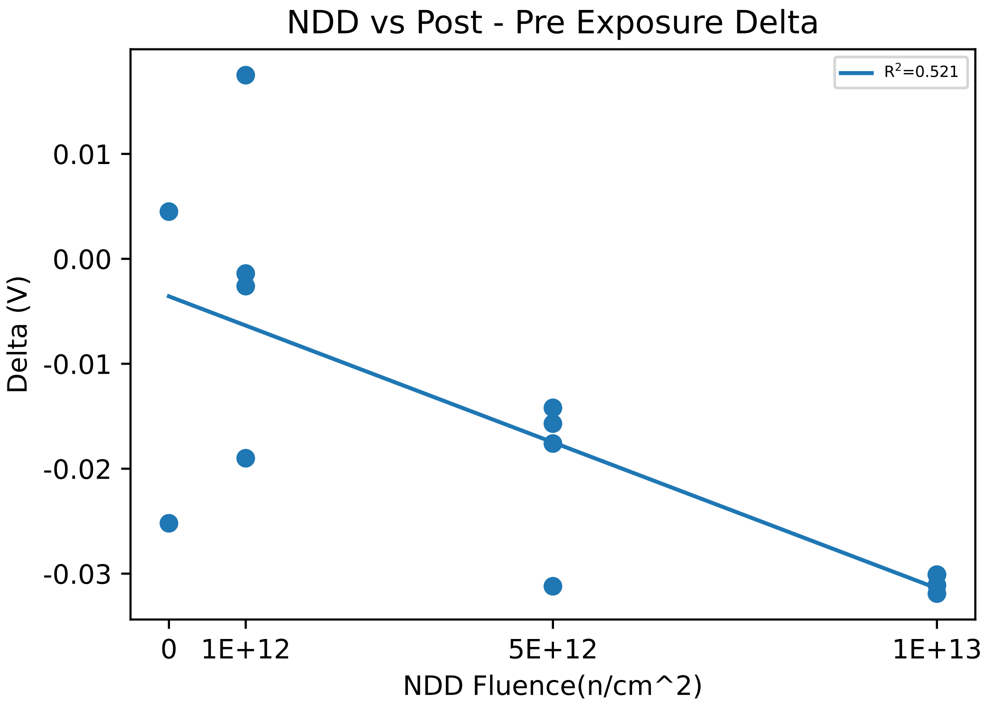
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	6.9944	7.0667	0.0723
2	0	Correlation	6.9872	7.0917	0.1045
30	1e+12	NDD unbiased	7.023	7.0262	0.0032
31	1e+12	NDD unbiased	7.0319	7.0173	-0.0146
32	1e+12	NDD unbiased	6.9858	6.98	-0.0058
33	1e+12	NDD unbiased	7.0012	6.997	-0.0042
44	5e+12	NDD unbiased	7.0412	7.0154	-0.0258
45	5e+12	NDD unbiased	7.032	7.0018	-0.0302
46	5e+12	NDD unbiased	7.0846	7.0575	-0.0271
47	5e+12	NDD unbiased	7.0302	7.0018	-0.0284
50	1e+13	NDD unbiased	6.9483	6.9078	-0.0405
51	1e+13	NDD unbiased	6.9515	6.9072	-0.0443
52	1e+13	NDD unbiased	6.9503	6.9087	-0.0416
53	1e+13	NDD unbiased	6.9988	6.9546	-0.0442

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	6.9872	6.9908	6.9944	0.0050912	7.0667	7.0792	7.0917	0.017678	0.0723	0.0884	0.1045	0.022769
1e+12	6.9858	7.0105	7.0319	0.020903	6.98	7.0051	7.0262	0.020734	-0.0146	-0.00535	0.0032	0.0073073
5e+12	7.0302	7.047	7.0846	0.025525	7.0018	7.0191	7.0575	0.026374	-0.0302	-0.027875	-0.0258	0.0018786
1e+13	6.9483	6.9622	6.9988	0.024419	6.9072	6.9196	6.9546	0.023358	-0.0443	-0.04265	-0.0405	0.0019018

Device Test: 60.22 V_BP5L(_V_BP5L IIM 5MHz VIN_10V)





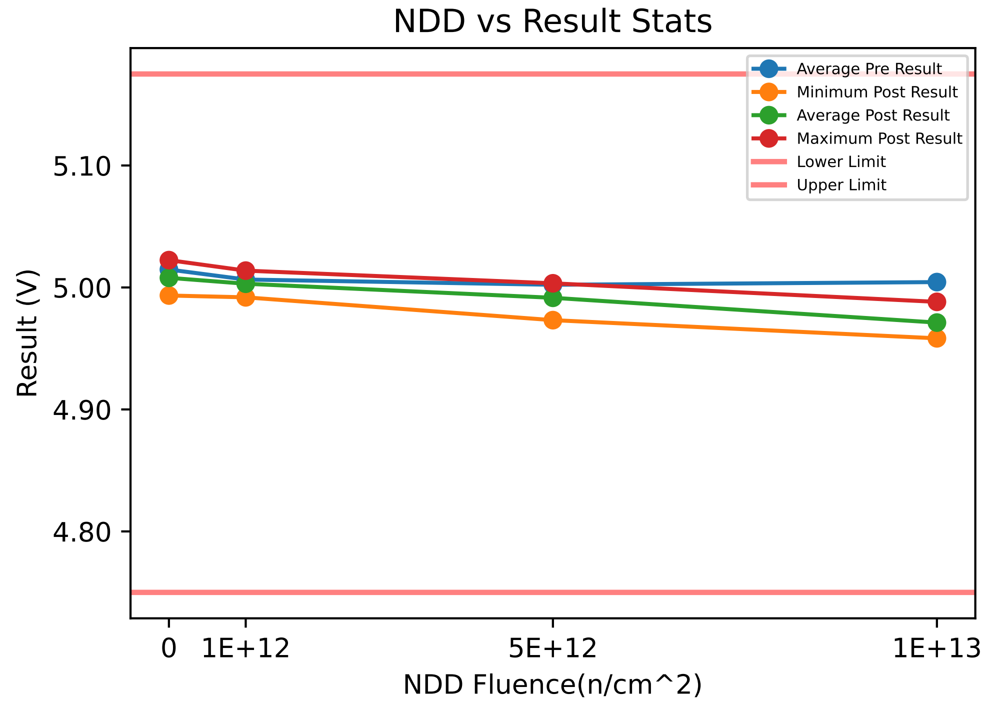
Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

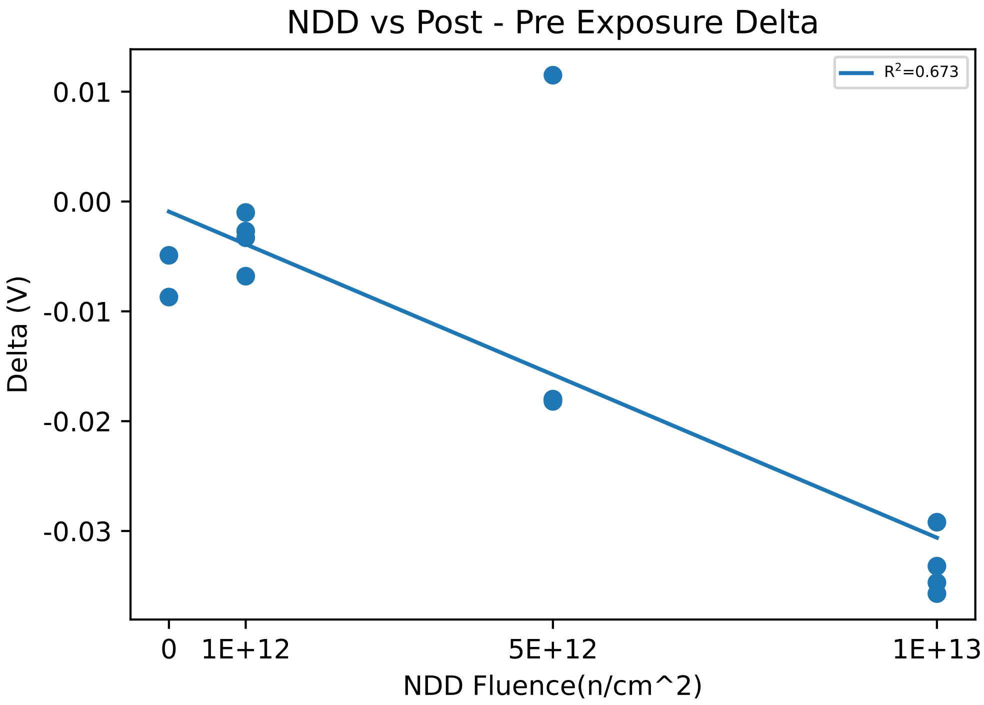
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	5.0238	4.9986	-0.0252
2	0	Correlation	5.0234	5.0279	0.0045
30	1e+12	NDD unbiased	5.0286	5.0096	-0.019
31	1e+12	NDD unbiased	5.0097	5.0272	0.0175
32	1e+12	NDD unbiased	5.0094	5.008	-0.0014
33	1e+12	NDD unbiased	4.9985	4.9959	-0.0026
44	5e+12	NDD unbiased	4.9995	4.9853	-0.0142
45	5e+12	NDD unbiased	5.0236	4.9924	-0.0312
46	5e+12	NDD unbiased	5.008	4.9923	-0.0157
47	5e+12	NDD unbiased	5.0099	4.9923	-0.0176
50	1e+13	NDD unbiased	4.9952	4.9641	-0.0311
51	1e+13	NDD unbiased	5.0072	4.9771	-0.0301
52	1e+13	NDD unbiased	5.0235	4.9934	-0.0301
53	1e+13	NDD unbiased	5.0023	4.9704	-0.0319

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.0234	5.0236	5.0238	0.00028284	4.9986	5.0132	5.0279	0.020718	-0.0252	-0.01035	0.0045	0.021001
1e+12	4.9985	5.0115	5.0286	0.012504	4.9959	5.0102	5.0272	0.012893	-0.019	-0.001375	0.0175	0.014927
5e+12	4.9995	5.0103	5.0236	0.0099828	4.9853	4.9906	4.9924	0.003517	-0.0312	-0.019675	-0.0142	0.0078083
1e+13	4.9952	5.007	5.0235	0.012022	4.9641	4.9763	4.9934	0.012605	-0.0319	-0.0308	-0.0301	0.00087178

Device Test: 60.23 V_BP5H(_V_BP5H IIM 5MHz VIN_10V)





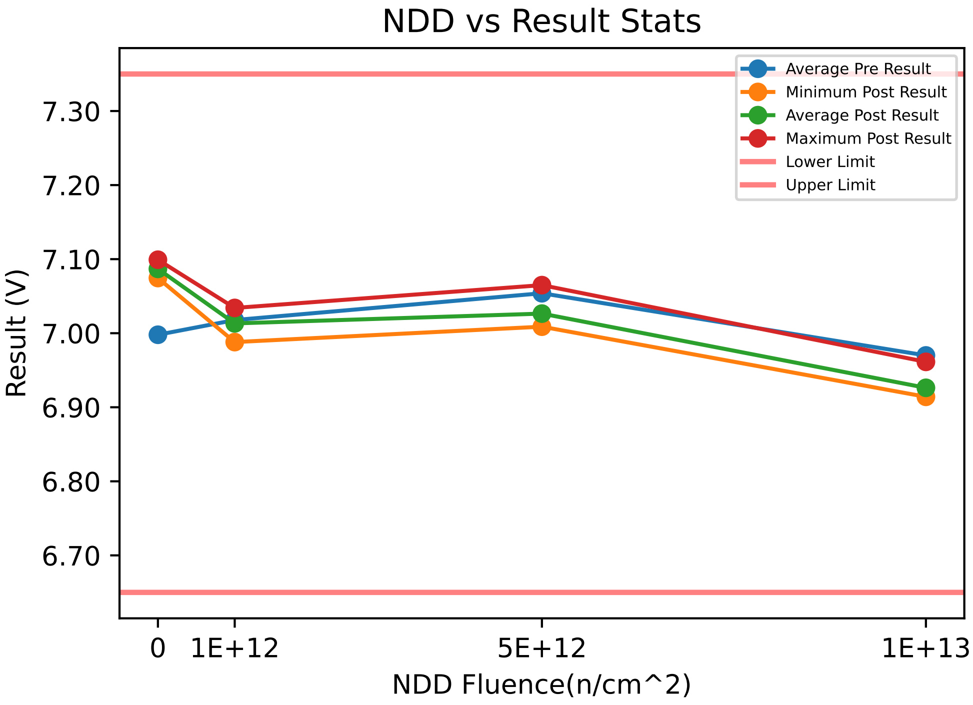
Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

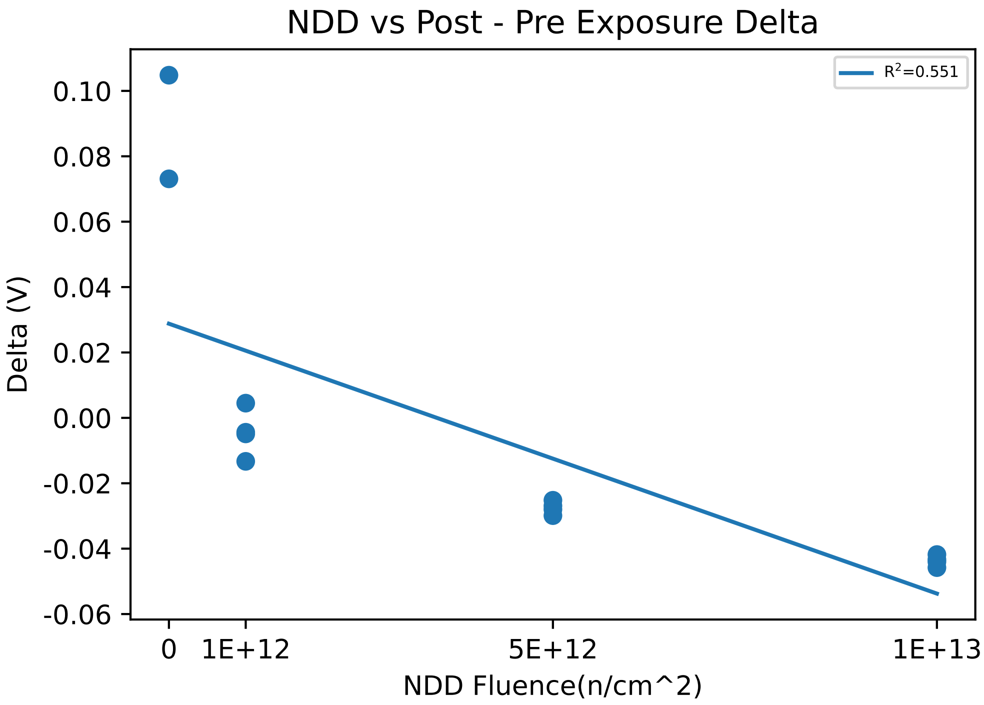
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	5.0021	4.9934	-0.0087
2	0	Correlation	5.0273	5.0224	-0.0049
30	1e+12	NDD unbiased	4.9954	4.9944	-0.001
31	1e+12	NDD unbiased	4.9987	4.9919	-0.0068
32	1e+12	NDD unbiased	5.0171	5.0138	-0.0033
33	1e+12	NDD unbiased	5.0148	5.0121	-0.0027
44	5e+12	NDD unbiased	5.0044	4.9864	-0.018
45	5e+12	NDD unbiased	4.9919	5.0034	0.0115
46	5e+12	NDD unbiased	4.9914	4.9732	-0.0182
47	5e+12	NDD unbiased	5.0211	5.0031	-0.018
50	1e+13	NDD unbiased	5.0214	4.9882	-0.0332
51	1e+13	NDD unbiased	4.994	4.9583	-0.0357
52	1e+13	NDD unbiased	5.0056	4.9764	-0.0292
53	1e+13	NDD unbiased	4.9966	4.9619	-0.0347

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.0021	5.0147	5.0273	0.017819	4.9934	5.0079	5.0224	0.020506	-0.0087	-0.0068	-0.0049	0.002687
1e+12	4.9954	5.0065	5.0171	0.011035	4.9919	5.003	5.0138	0.011498	-0.0068	-0.00345	-0.001	0.0024365
5e+12	4.9914	5.0022	5.0211	0.013962	4.9732	4.9915	5.0034	0.014572	-0.0182	-0.010675	0.0115	0.014784
1e+13	4.994	5.0044	5.0214	0.012375	4.9583	4.9712	4.9882	0.013771	-0.0357	-0.0332	-0.0292	0.0028577

Device Test: 60.3 V_BP7L(_V_BP7L PWM 1MHz VIN_10V)


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

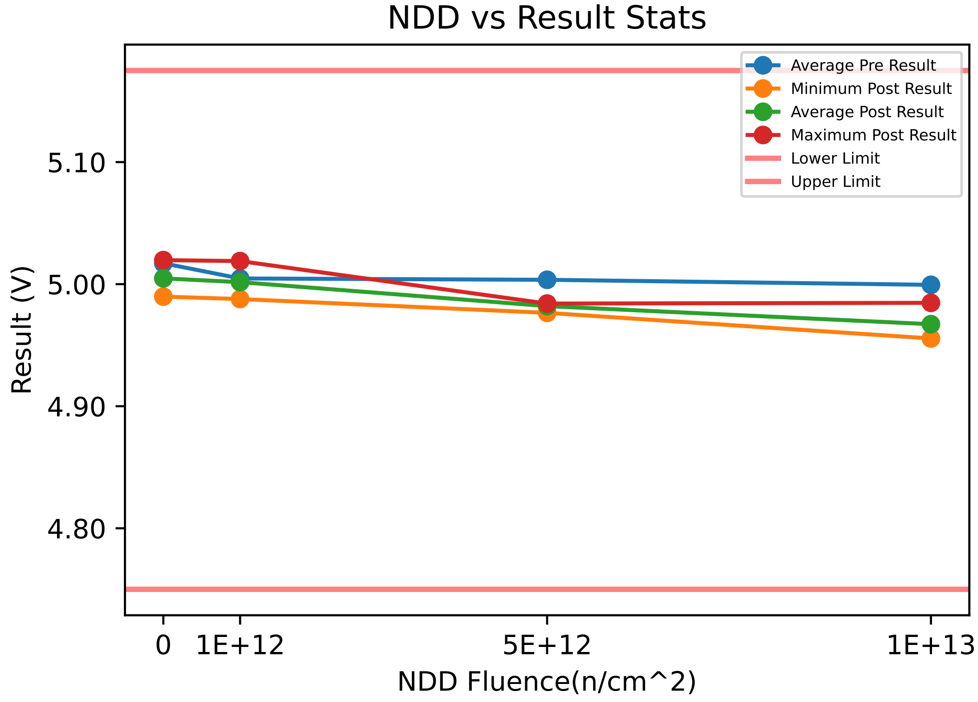
Test Results (Lower Limit = 6.65, Upper Limit = 7.35 (V))

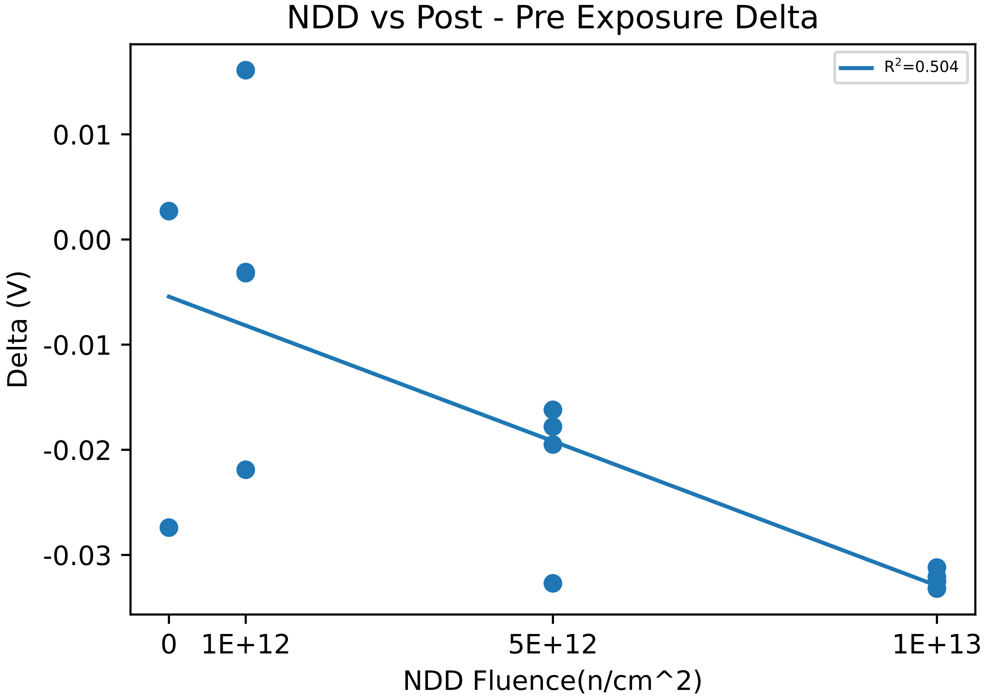
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	7.0014	7.0745	0.0731
2	0	Correlation	6.9944	7.0992	0.1048
30	1e+12	NDD unbiased	7.0296	7.0341	0.0045
31	1e+12	NDD unbiased	7.0385	7.0252	-0.0133
32	1e+12	NDD unbiased	6.9929	6.988	-0.0049
33	1e+12	NDD unbiased	7.01	7.0056	-0.0044
44	5e+12	NDD unbiased	7.0485	7.0233	-0.0252
45	5e+12	NDD unbiased	7.0387	7.0088	-0.0299
46	5e+12	NDD unbiased	7.0918	7.0649	-0.0269
47	5e+12	NDD unbiased	7.0368	7.0088	-0.028
50	1e+13	NDD unbiased	6.9564	6.9146	-0.0418
51	1e+13	NDD unbiased	6.9581	6.9141	-0.044
52	1e+13	NDD unbiased	6.9583	6.915	-0.0433
53	1e+13	NDD unbiased	7.0071	6.9613	-0.0458

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	6.9944	6.9979	7.0014	0.0049497	7.0745	7.0869	7.0992	0.017466	0.0731	0.08895	0.1048	0.022415
1e+12	6.9929	7.0177	7.0385	0.020401	6.988	7.0132	7.0341	0.020604	-0.0133	-0.004525	0.0045	0.0072711
5e+12	7.0368	7.054	7.0918	0.025749	7.0088	7.0264	7.0649	0.026529	-0.0299	-0.0275	-0.0252	0.0019715
1e+13	6.9564	6.97	7.0071	0.024765	6.9141	6.9262	6.9613	0.02337	-0.0458	-0.043725	-0.0418	0.0016601

Device Test: 60.4 V_BP5L(_V_BP5L PWM 1MHz VIN_10V)





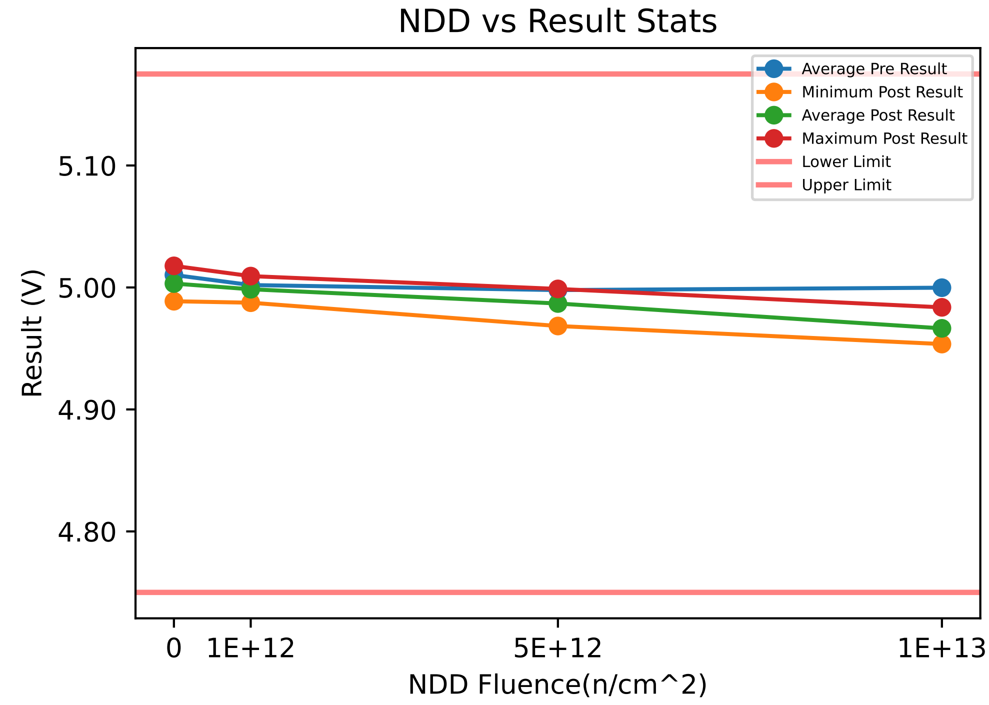
Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

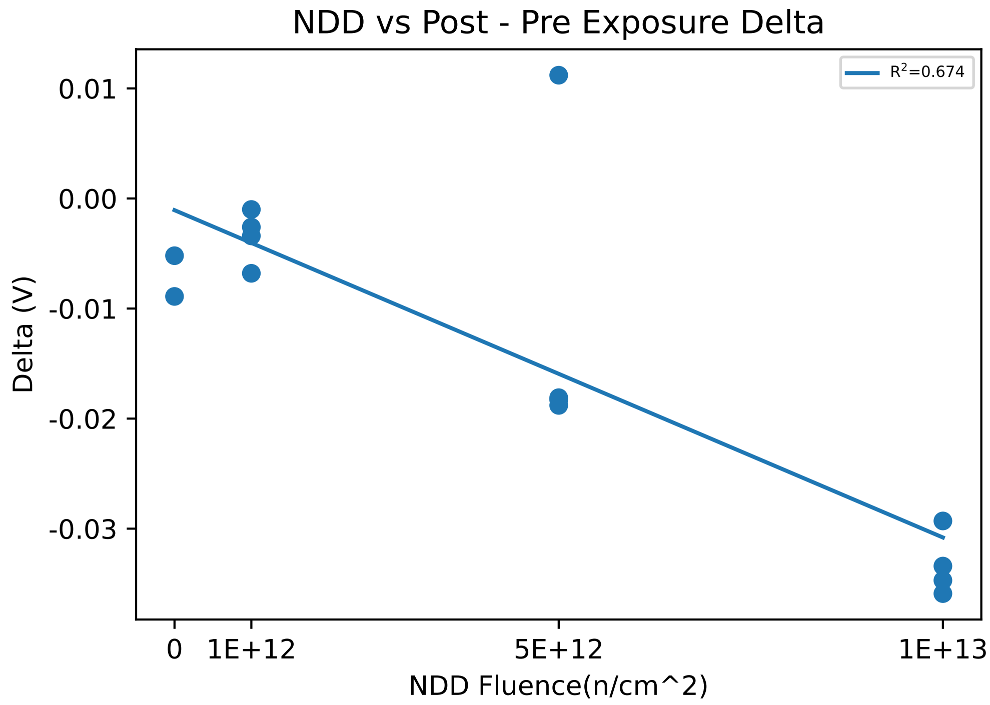
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	5.0172	4.9898	-0.0274
2	0	Correlation	5.017	5.0197	0.0027
30	1e+12	NDD unbiased	5.0223	5.0004	-0.0219
31	1e+12	NDD unbiased	5.0028	5.0189	0.0161
32	1e+12	NDD unbiased	5.0026	4.9995	-0.0031
33	1e+12	NDD unbiased	4.991	4.9878	-0.0032
44	5e+12	NDD unbiased	4.9927	4.9765	-0.0162
45	5e+12	NDD unbiased	5.0168	4.9841	-0.0327
46	5e+12	NDD unbiased	5.0013	4.9835	-0.0178
47	5e+12	NDD unbiased	5.0035	4.984	-0.0195
50	1e+13	NDD unbiased	4.9876	4.9555	-0.0321
51	1e+13	NDD unbiased	4.9996	4.9671	-0.0325
52	1e+13	NDD unbiased	5.0159	4.9847	-0.0312
53	1e+13	NDD unbiased	4.9947	4.9615	-0.0332

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.017	5.0171	5.0172	0.00014142	4.9898	5.0047	5.0197	0.021142	-0.0274	-0.01235	0.0027	0.021284
1e+12	4.991	5.0047	5.0223	0.01298	4.9878	5.0016	5.0189	0.012853	-0.0219	-0.003025	0.0161	0.015514
5e+12	4.9927	5.0036	5.0168	0.0099724	4.9765	4.982	4.9841	0.0036927	-0.0327	-0.02155	-0.0162	0.0075545
1e+13	4.9876	4.9994	5.0159	0.012022	4.9555	4.9672	4.9847	0.012592	-0.0332	-0.03225	-0.0312	0.00083467

Device Test: 60.5 V_BP5H(_V_BP5H PWM 1MHz VIN_10V)





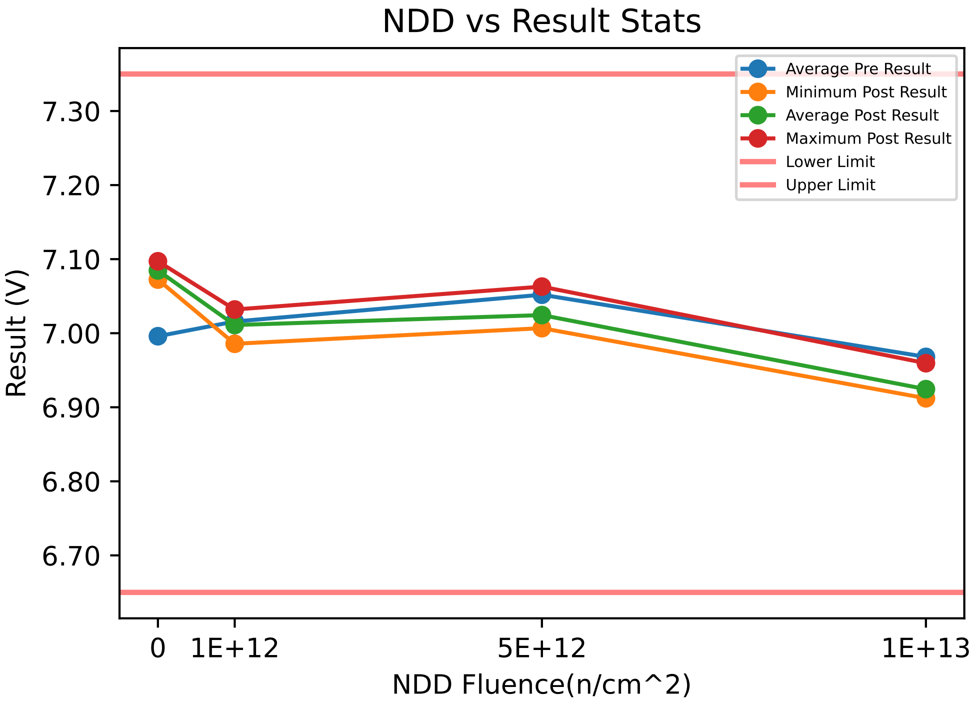
Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

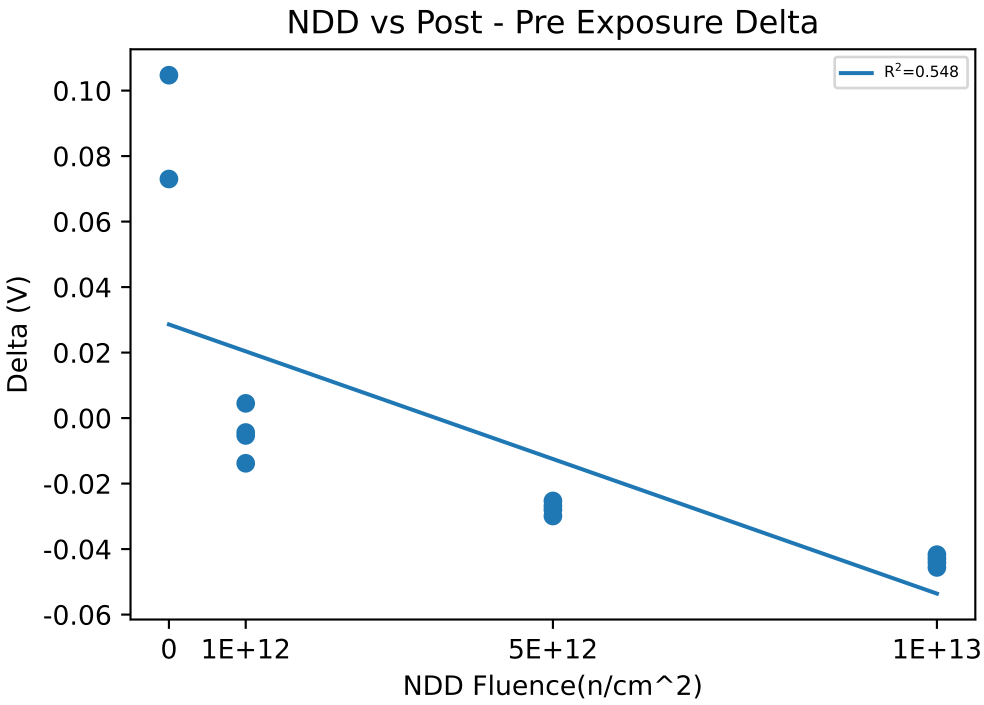
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	4.9976	4.9887	-0.0089
2	0	Correlation	5.0229	5.0177	-0.0052
30	1e+12	NDD unbiased	4.9908	4.9898	-0.001
31	1e+12	NDD unbiased	4.9943	4.9875	-0.0068
32	1e+12	NDD unbiased	5.0127	5.0093	-0.0034
33	1e+12	NDD unbiased	5.0101	5.0075	-0.0026
44	5e+12	NDD unbiased	4.9999	4.9818	-0.0181
45	5e+12	NDD unbiased	4.9876	4.9988	0.0112
46	5e+12	NDD unbiased	4.9872	4.9684	-0.0188
47	5e+12	NDD unbiased	5.0167	4.9984	-0.0183
50	1e+13	NDD unbiased	5.0171	4.9837	-0.0334
51	1e+13	NDD unbiased	4.9895	4.9536	-0.0359
52	1e+13	NDD unbiased	5.001	4.9717	-0.0293
53	1e+13	NDD unbiased	4.9916	4.9569	-0.0347

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.9976	5.0103	5.0229	0.01789	4.9887	5.0032	5.0177	0.020506	-0.0089	-0.00705	-0.0052	0.0026163
1e+12	4.9908	5.002	5.0127	0.011028	4.9875	4.9985	5.0093	0.011465	-0.0068	-0.00345	-0.001	0.0024461
5e+12	4.9872	4.9978	5.0167	0.013881	4.9684	4.9869	4.9988	0.01463	-0.0188	-0.011	0.0112	0.014803
1e+13	4.9895	4.9998	5.0171	0.012571	4.9536	4.9665	4.9837	0.013922	-0.0359	-0.033325	-0.0293	0.002871

Device Test: 60.6 V_BP7L(_V_BP7L PWM 2MHz VIN_10V)





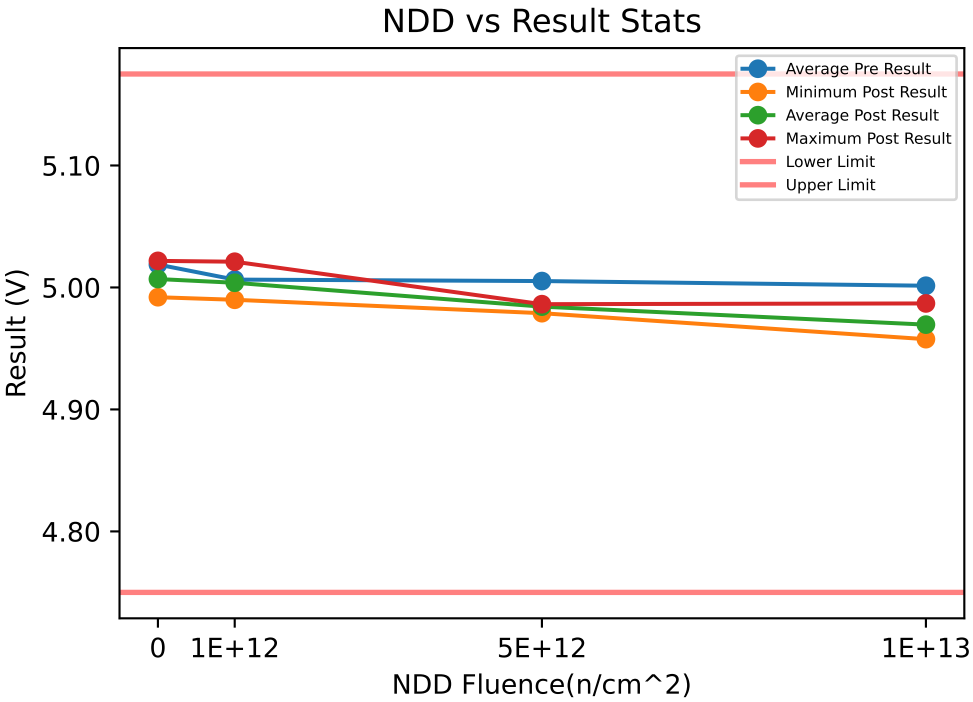
Test Results (Lower Limit = 6.65, Upper Limit = 7.35 (V))

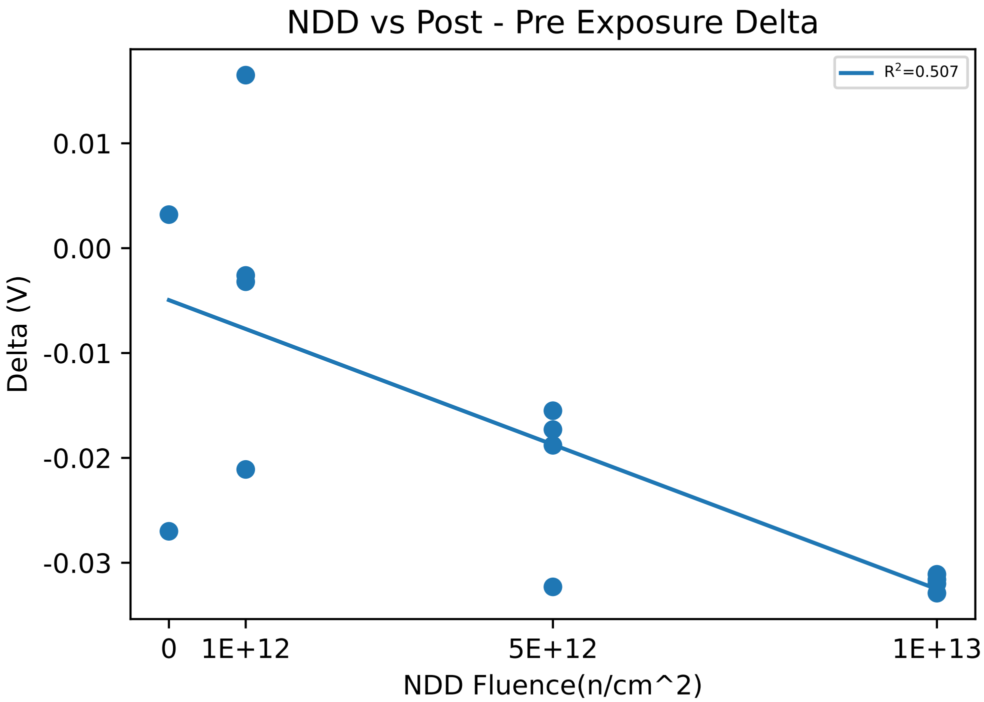
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	6.9994	7.0724	0.073
2	0	Correlation	6.9924	7.0971	0.1047
30	1e+12	NDD unbiased	7.0275	7.032	0.0045
31	1e+12	NDD unbiased	7.0368	7.023	-0.0138
32	1e+12	NDD unbiased	6.991	6.9857	-0.0053
33	1e+12	NDD unbiased	7.0078	7.0034	-0.0044
44	5e+12	NDD unbiased	7.0465	7.0212	-0.0253
45	5e+12	NDD unbiased	7.0368	7.0069	-0.0299
46	5e+12	NDD unbiased	7.0897	7.0629	-0.0268
47	5e+12	NDD unbiased	7.0348	7.0068	-0.028
50	1e+13	NDD unbiased	6.9545	6.9128	-0.0417
51	1e+13	NDD unbiased	6.9562	6.9121	-0.0441
52	1e+13	NDD unbiased	6.9562	6.9133	-0.0429
53	1e+13	NDD unbiased	7.0051	6.9595	-0.0456

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	6.9924	6.9959	6.9994	0.0049497	7.0724	7.0847	7.0971	0.017466	0.073	0.08885	0.1047	0.022415
1e+12	6.991	7.0158	7.0368	0.020469	6.9857	7.011	7.032	0.020679	-0.0138	-0.00475	0.0045	0.0074809
5e+12	7.0348	7.0519	7.0897	0.02568	7.0068	7.0244	7.0629	0.026511	-0.0299	-0.0275	-0.0253	0.0019442
1e+13	6.9545	6.968	7.0051	0.024746	6.9121	6.9244	6.9595	0.023389	-0.0456	-0.043575	-0.0417	0.0016681

Device Test: 60.7 V_BP5L(_V_BP5L PWM 2MHz VIN_10V)





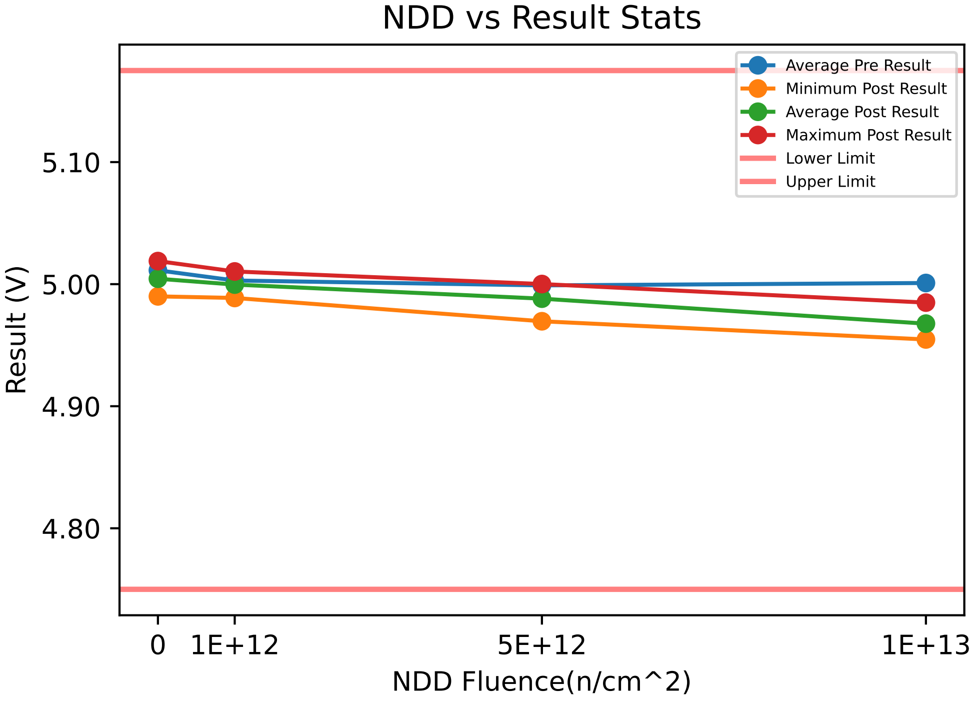
Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

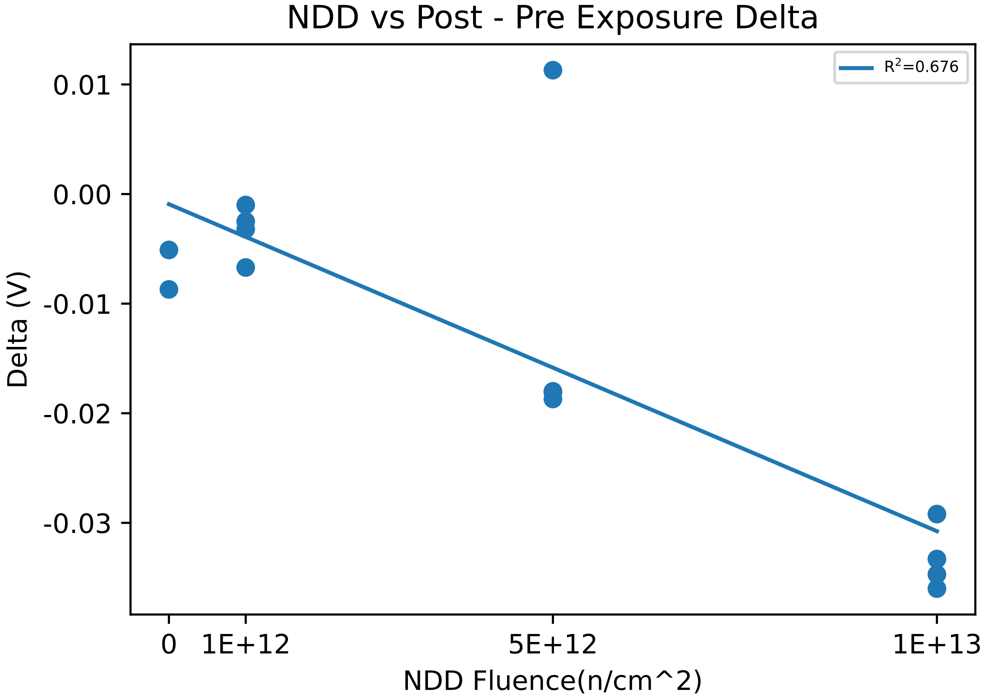
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	5.019	4.992	-0.027
2	0	Correlation	5.0186	5.0218	0.0032
30	1e+12	NDD unbiased	5.0238	5.0027	-0.0211
31	1e+12	NDD unbiased	5.0046	5.0211	0.0165
32	1e+12	NDD unbiased	5.0043	5.0017	-0.0026
33	1e+12	NDD unbiased	4.9931	4.9899	-0.0032
44	5e+12	NDD unbiased	4.9944	4.9789	-0.0155
45	5e+12	NDD unbiased	5.0185	4.9862	-0.0323
46	5e+12	NDD unbiased	5.003	4.9857	-0.0173
47	5e+12	NDD unbiased	5.0051	4.9863	-0.0188
50	1e+13	NDD unbiased	4.9896	4.9576	-0.032
51	1e+13	NDD unbiased	5.0014	4.9698	-0.0316
52	1e+13	NDD unbiased	5.018	4.9869	-0.0311
53	1e+13	NDD unbiased	4.9967	4.9638	-0.0329

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.0186	5.0188	5.019	0.00028284	4.992	5.0069	5.0218	0.021072	-0.027	-0.0119	0.0032	0.021355
1e+12	4.9931	5.0065	5.0238	0.012745	4.9899	5.0038	5.0211	0.012886	-0.0211	-0.0026	0.0165	0.015356
5e+12	4.9944	5.0053	5.0185	0.0099728	4.9789	4.9843	4.9863	0.0035929	-0.0323	-0.020975	-0.0155	0.0076696
1e+13	4.9896	5.0014	5.018	0.012068	4.9576	4.9695	4.9869	0.012609	-0.0329	-0.0319	-0.0311	0.00076158

Device Test: 60.8 V_BP5H(_V_BP5H PWM 2MHz VIN_10V)


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

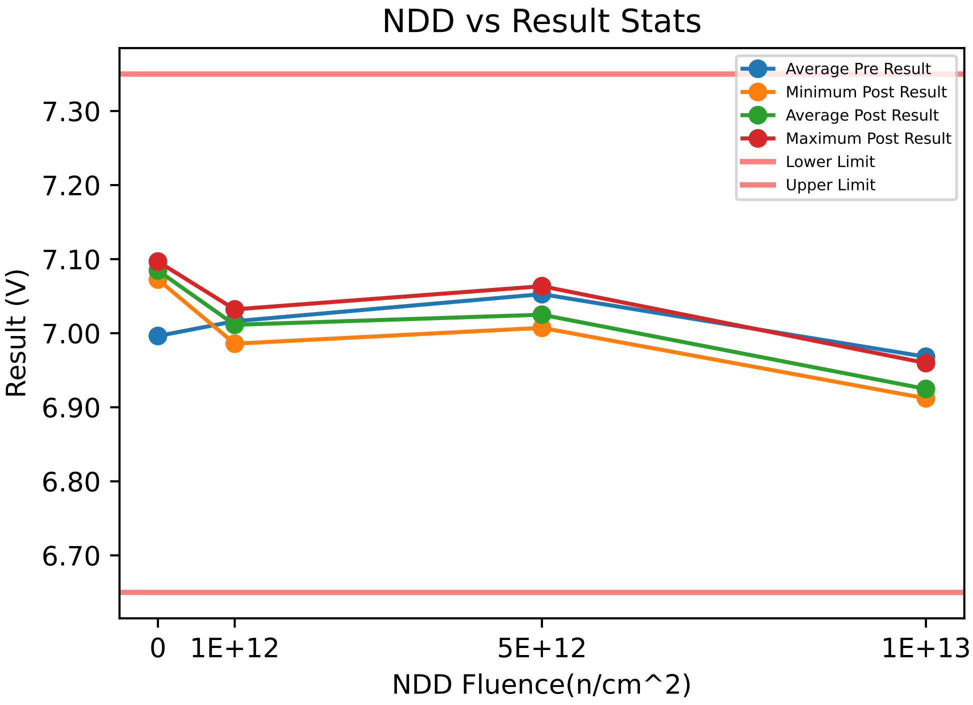
Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

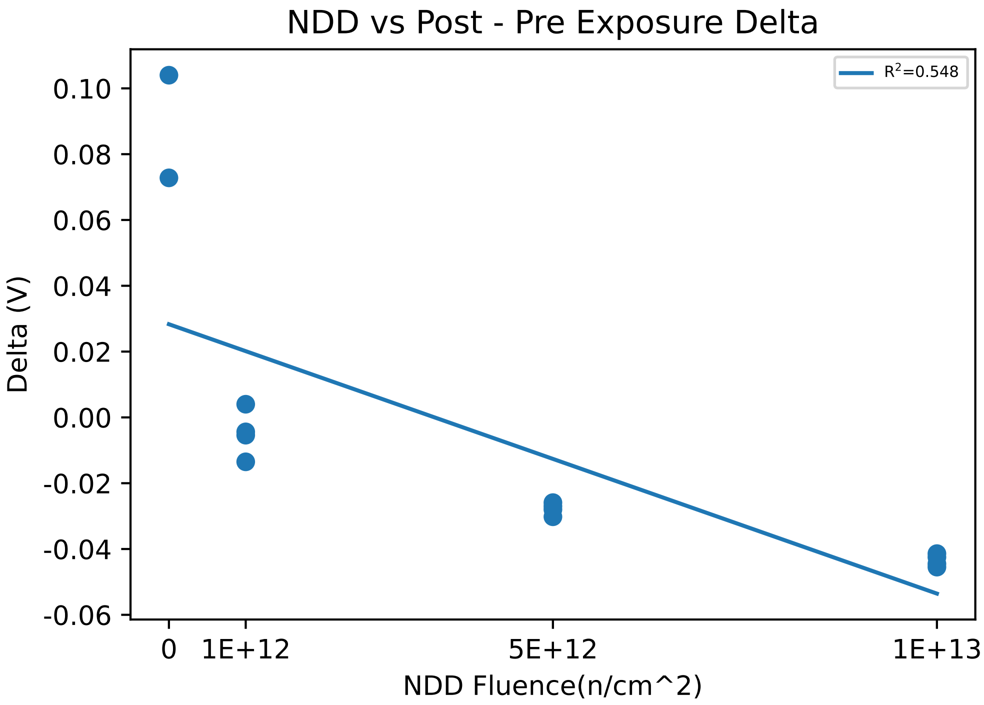
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	4.9987	4.99	-0.0087
2	0	Correlation	5.024	5.0189	-0.0051
30	1e+12	NDD unbiased	4.9919	4.9909	-0.001
31	1e+12	NDD unbiased	4.9954	4.9887	-0.0067
32	1e+12	NDD unbiased	5.0136	5.0104	-0.0032
33	1e+12	NDD unbiased	5.0111	5.0086	-0.0025
44	5e+12	NDD unbiased	5.0012	4.9831	-0.0181
45	5e+12	NDD unbiased	4.9888	5.0001	0.0113
46	5e+12	NDD unbiased	4.9883	4.9696	-0.0187
47	5e+12	NDD unbiased	5.0177	4.9997	-0.018
50	1e+13	NDD unbiased	5.0182	4.9849	-0.0333
51	1e+13	NDD unbiased	4.9907	4.9547	-0.036
52	1e+13	NDD unbiased	5.0021	4.9729	-0.0292
53	1e+13	NDD unbiased	4.9928	4.9581	-0.0347

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.9987	5.0114	5.024	0.01789	4.99	5.0045	5.0189	0.020435	-0.0087	-0.0069	-0.0051	0.0025456
1e+12	4.9919	5.003	5.0136	0.010938	4.9887	4.9996	5.0104	0.011433	-0.0067	-0.00335	-0.001	0.0024145
5e+12	4.9883	4.999	5.0177	0.013821	4.9696	4.9881	5.0001	0.014672	-0.0187	-0.010875	0.0113	0.014787
1e+13	4.9907	5.001	5.0182	0.012522	4.9547	4.9676	4.9849	0.013953	-0.036	-0.0333	-0.0292	0.0029473

Device Test: 60.9 V_BP7L(_V_BP7L PWM 5MHz VIN_10V)





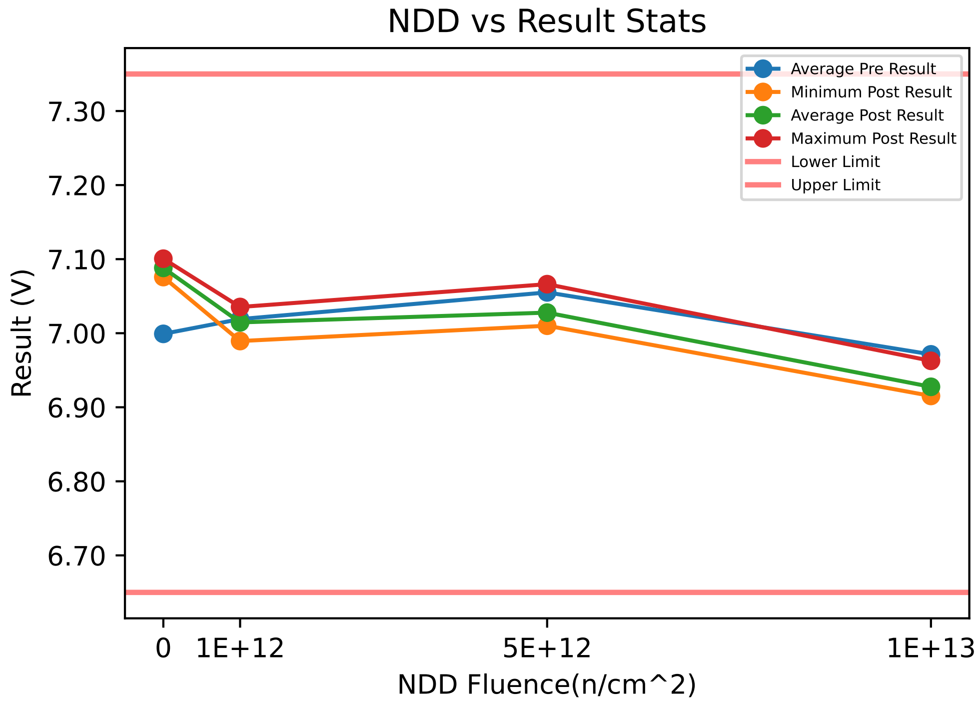
Test Results (Lower Limit = 6.65, Upper Limit = 7.35 (V))

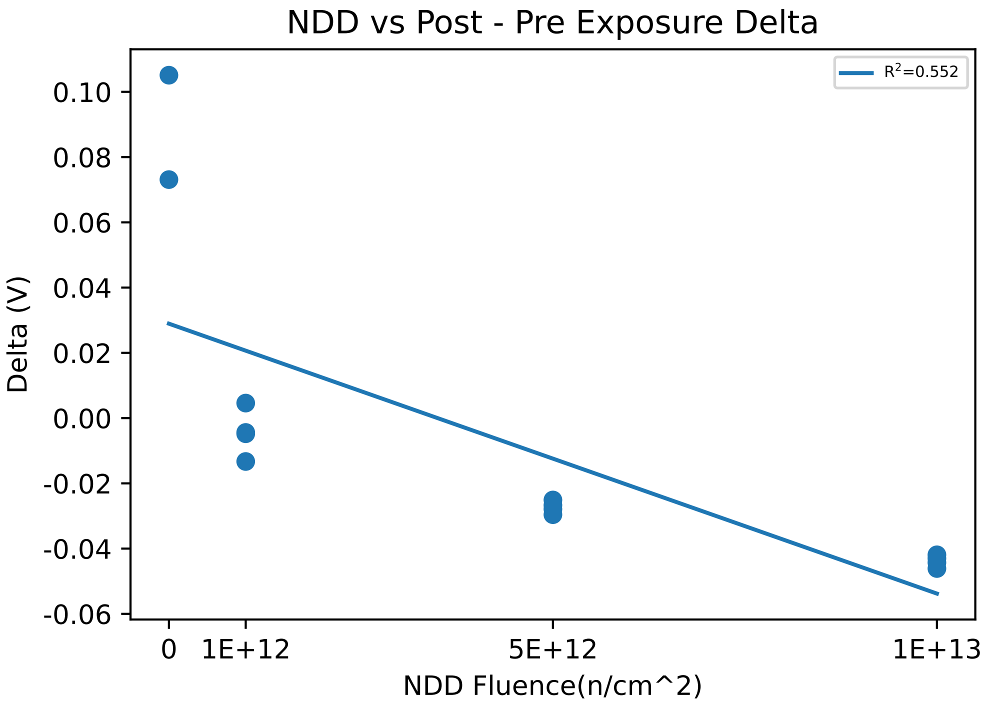
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	6.9997	7.0725	0.0728
2	0	Correlation	6.9928	7.0968	0.104
30	1e+12	NDD unbiased	7.0282	7.0322	0.004
31	1e+12	NDD unbiased	7.0369	7.0234	-0.0135
32	1e+12	NDD unbiased	6.9913	6.9859	-0.0054
33	1e+12	NDD unbiased	7.0083	7.0039	-0.0044
44	5e+12	NDD unbiased	7.0476	7.0217	-0.0259
45	5e+12	NDD unbiased	7.0375	7.0073	-0.0302
46	5e+12	NDD unbiased	7.0905	7.0635	-0.027
47	5e+12	NDD unbiased	7.0354	7.0074	-0.028
50	1e+13	NDD unbiased	6.9545	6.9131	-0.0414
51	1e+13	NDD unbiased	6.9566	6.9121	-0.0445
52	1e+13	NDD unbiased	6.9565	6.914	-0.0425
53	1e+13	NDD unbiased	7.0052	6.9597	-0.0455

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	6.9928	6.9962	6.9997	0.004879	7.0725	7.0846	7.0968	0.017183	0.0728	0.0884	0.104	0.022062
1e+12	6.9913	7.0162	7.0369	0.020452	6.9859	7.0114	7.0322	0.020681	-0.0135	-0.004825	0.004	0.0071565
5e+12	7.0354	7.0527	7.0905	0.025724	7.0073	7.025	7.0635	0.026559	-0.0302	-0.027775	-0.0259	0.0018301
1e+13	6.9545	6.9682	7.0052	0.024686	6.9121	6.9247	6.9597	0.02333	-0.0455	-0.043475	-0.0414	0.0018626

Device Test: 61.0 V_BP7L(_V_BP7L PWM 500kHz VIN_12V)


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

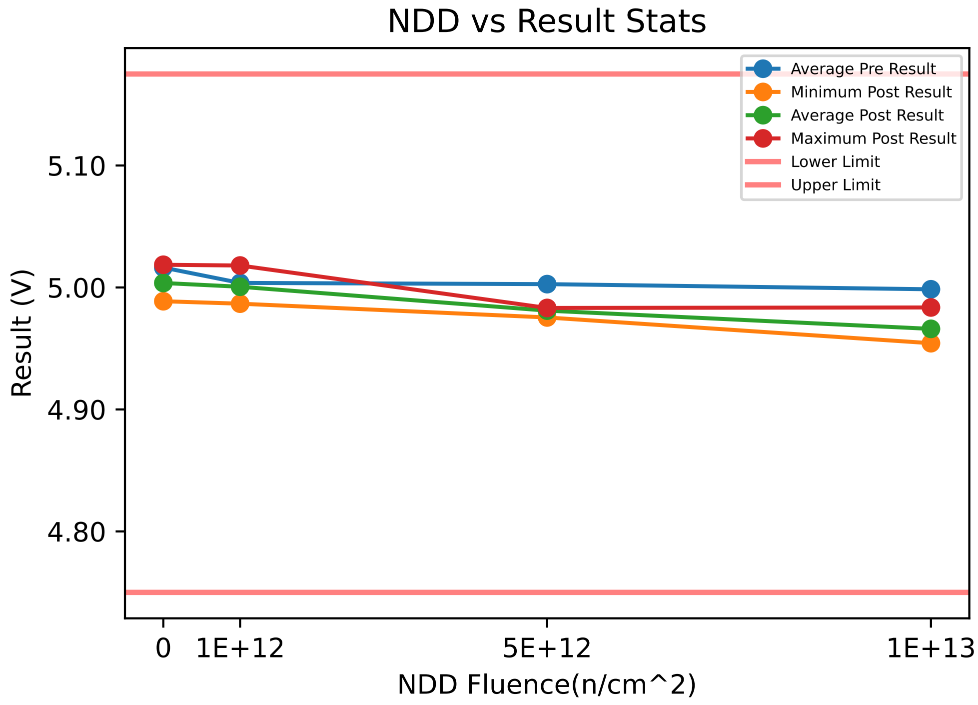
Test Results (Lower Limit = 6.65, Upper Limit = 7.35 (V))

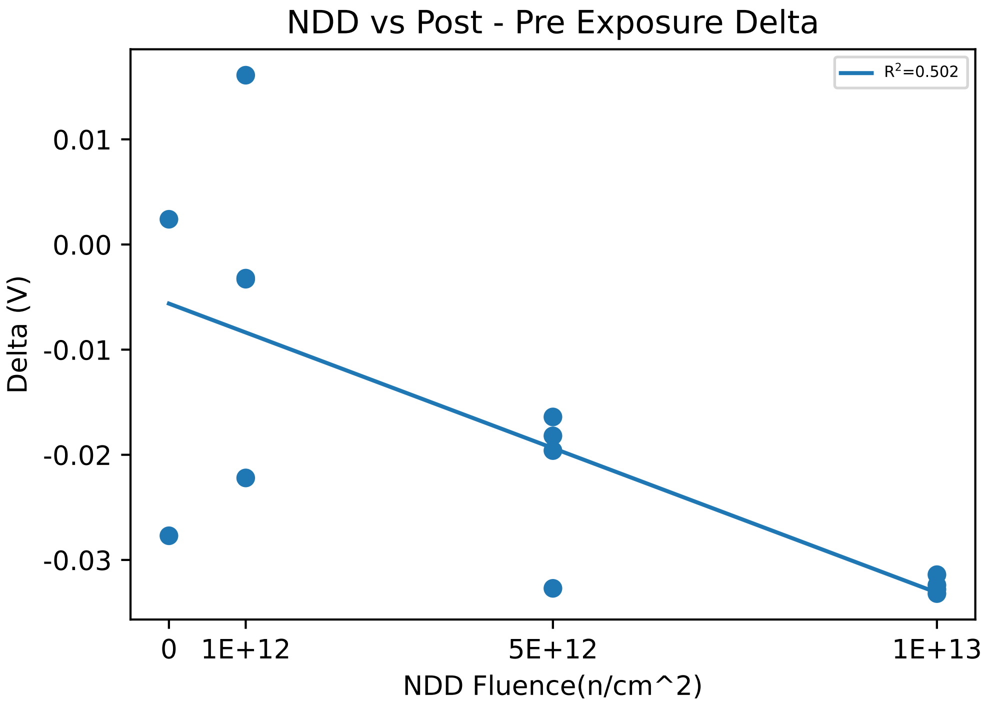
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	7.0027	7.0758	0.0731
2	0	Correlation	6.9955	7.1006	0.1051
30	1e+12	NDD unbiased	7.0308	7.0354	0.0046
31	1e+12	NDD unbiased	7.0397	7.0264	-0.0133
32	1e+12	NDD unbiased	6.9942	6.9894	-0.0048
33	1e+12	NDD unbiased	7.0115	7.0071	-0.0044
44	5e+12	NDD unbiased	7.0497	7.0246	-0.0251
45	5e+12	NDD unbiased	7.0398	7.0102	-0.0296
46	5e+12	NDD unbiased	7.0929	7.0662	-0.0267
47	5e+12	NDD unbiased	7.038	7.0101	-0.0279
50	1e+13	NDD unbiased	6.9578	6.9159	-0.0419
51	1e+13	NDD unbiased	6.9596	6.9153	-0.0443
52	1e+13	NDD unbiased	6.9595	6.9165	-0.043
53	1e+13	NDD unbiased	7.0088	6.9627	-0.0461

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	6.9955	6.9991	7.0027	0.0050912	7.0758	7.0882	7.1006	0.017536	0.0731	0.0891	0.1051	0.022627
1e+12	6.9942	7.0191	7.0397	0.020322	6.9894	7.0146	7.0354	0.02052	-0.0133	-0.004475	0.0046	0.0073109
5e+12	7.038	7.0551	7.0929	0.02572	7.0101	7.0278	7.0662	0.026507	-0.0296	-0.027325	-0.0251	0.0019015
1e+13	6.9578	6.9714	7.0088	0.02493	6.9153	6.9276	6.9627	0.023405	-0.0461	-0.043825	-0.0419	0.0018062

Device Test: 61.1 V_BP5L(_V_BP5L PWM 500kHz VIN_12V)





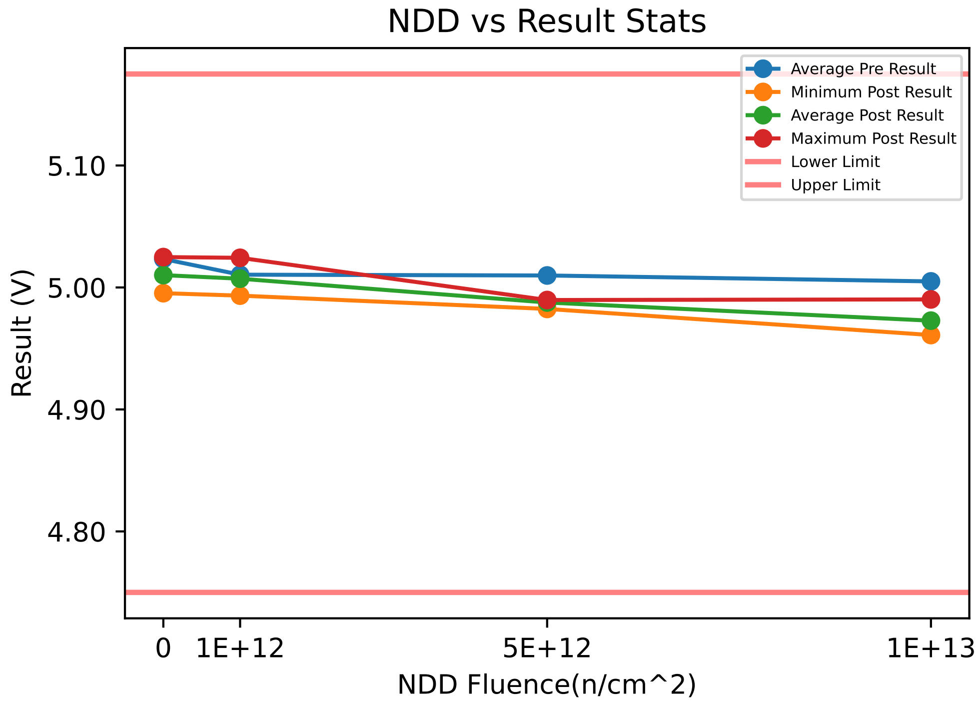
Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

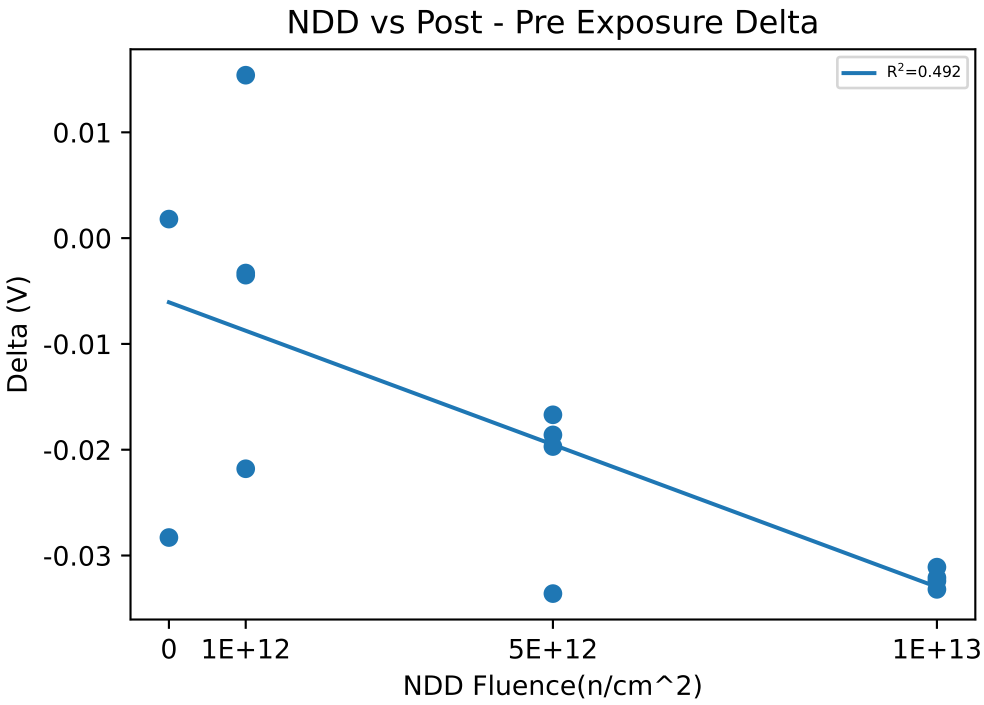
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	5.0164	4.9887	-0.0277
2	0	Correlation	5.0162	5.0186	0.0024
30	1e+12	NDD unbiased	5.0214	4.9992	-0.0222
31	1e+12	NDD unbiased	5.0019	5.018	0.0161
32	1e+12	NDD unbiased	5.0017	4.9984	-0.0033
33	1e+12	NDD unbiased	4.9899	4.9867	-0.0032
44	5e+12	NDD unbiased	4.9918	4.9754	-0.0164
45	5e+12	NDD unbiased	5.0159	4.9832	-0.0327
46	5e+12	NDD unbiased	5.0005	4.9823	-0.0182
47	5e+12	NDD unbiased	5.0027	4.9831	-0.0196
50	1e+13	NDD unbiased	4.9867	4.9543	-0.0324
51	1e+13	NDD unbiased	4.9987	4.9659	-0.0328
52	1e+13	NDD unbiased	5.015	4.9836	-0.0314
53	1e+13	NDD unbiased	4.9936	4.9604	-0.0332

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.0162	5.0163	5.0164	0.00014142	4.9887	5.0037	5.0186	0.021142	-0.0277	-0.01265	0.0024	0.021284
1e+12	4.9899	5.0037	5.0214	0.013051	4.9867	5.0006	5.018	0.012946	-0.0222	-0.00315	0.0161	0.015636
5e+12	4.9918	5.0027	5.0159	0.0099647	4.9754	4.981	4.9832	0.003755	-0.0327	-0.021725	-0.0164	0.007433
1e+13	4.9867	4.9985	5.015	0.012049	4.9543	4.9661	4.9836	0.012623	-0.0332	-0.03245	-0.0314	0.00077244

Device Test: 61.10 V_BP5L(_V_BP5L PWM 5MHz VIN_12V)


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

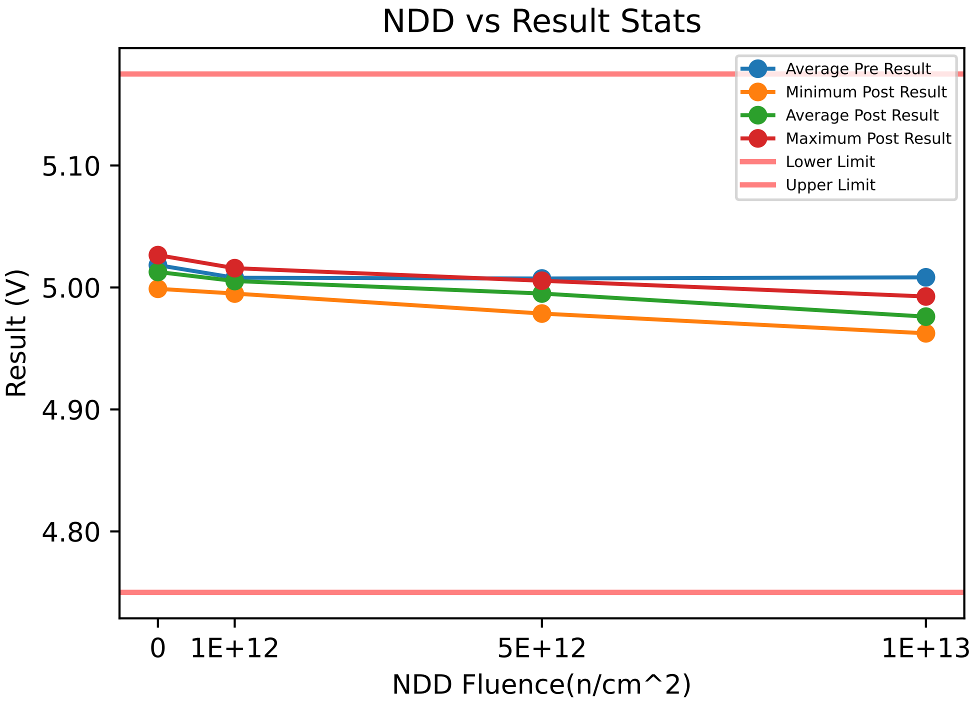
Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

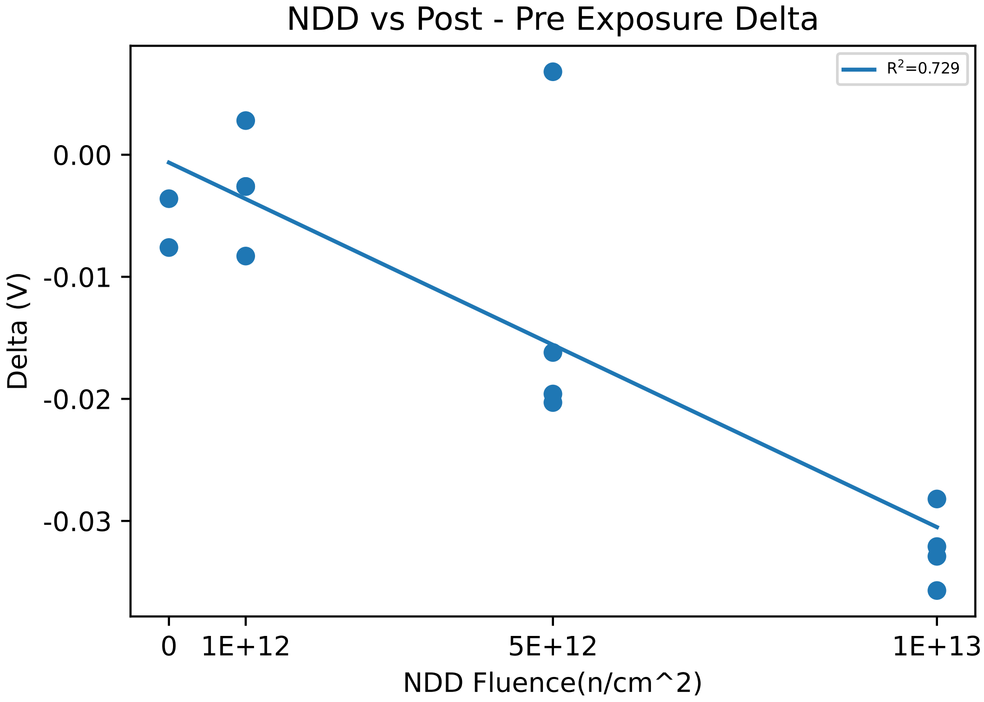
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	5.0236	4.9953	-0.0283
2	0	Correlation	5.0231	5.0249	0.0018
30	1e+12	NDD unbiased	5.0278	5.006	-0.0218
31	1e+12	NDD unbiased	5.0089	5.0243	0.0154
32	1e+12	NDD unbiased	5.0086	5.0051	-0.0035
33	1e+12	NDD unbiased	4.9966	4.9933	-0.0033
44	5e+12	NDD unbiased	4.9991	4.9824	-0.0167
45	5e+12	NDD unbiased	5.0233	4.9897	-0.0336
46	5e+12	NDD unbiased	5.0076	4.989	-0.0186
47	5e+12	NDD unbiased	5.0093	4.9896	-0.0197
50	1e+13	NDD unbiased	4.9931	4.961	-0.0321
51	1e+13	NDD unbiased	5.0053	4.9729	-0.0324
52	1e+13	NDD unbiased	5.0213	4.9902	-0.0311
53	1e+13	NDD unbiased	5.0002	4.967	-0.0332

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.0231	5.0234	5.0236	0.00035355	4.9953	5.0101	5.0249	0.02093	-0.0283	-0.01325	0.0018	0.021284
1e+12	4.9966	5.0105	5.0278	0.012893	4.9933	5.0072	5.0243	0.012799	-0.0218	-0.0033	0.0154	0.015187
5e+12	4.9991	5.0098	5.0233	0.01003	4.9824	4.9877	4.9897	0.0035302	-0.0336	-0.02215	-0.0167	0.0077333
1e+13	4.9931	5.005	5.0213	0.011978	4.961	4.9728	4.9902	0.012592	-0.0332	-0.0322	-0.0311	0.00086795

Device Test: 61.11 V_BP5H(_V_BP5H PWM 5MHz VIN_12V)





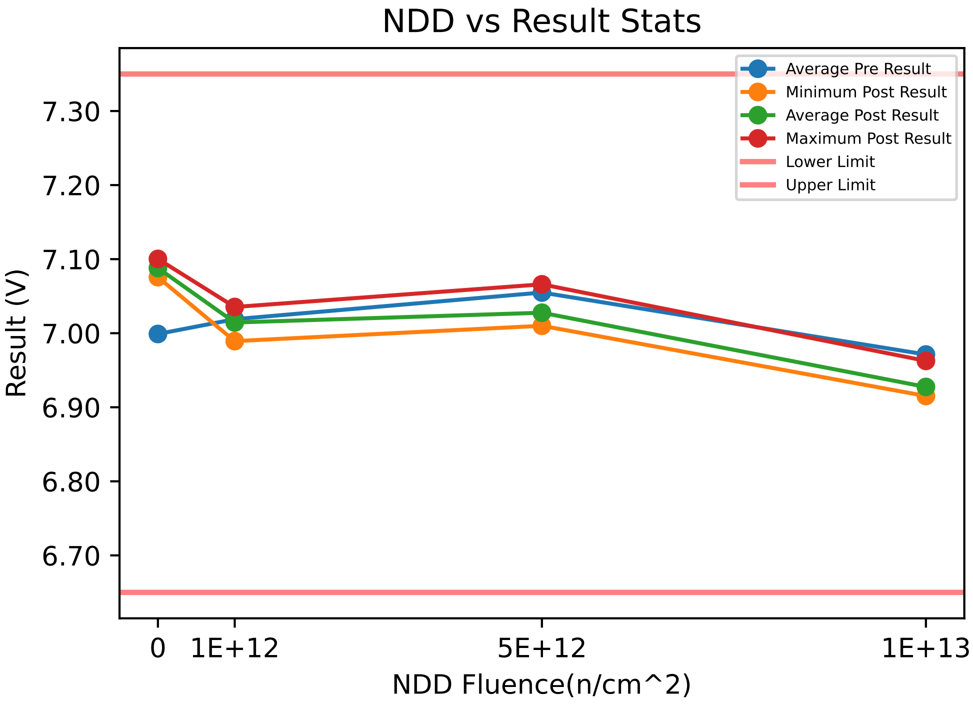
Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

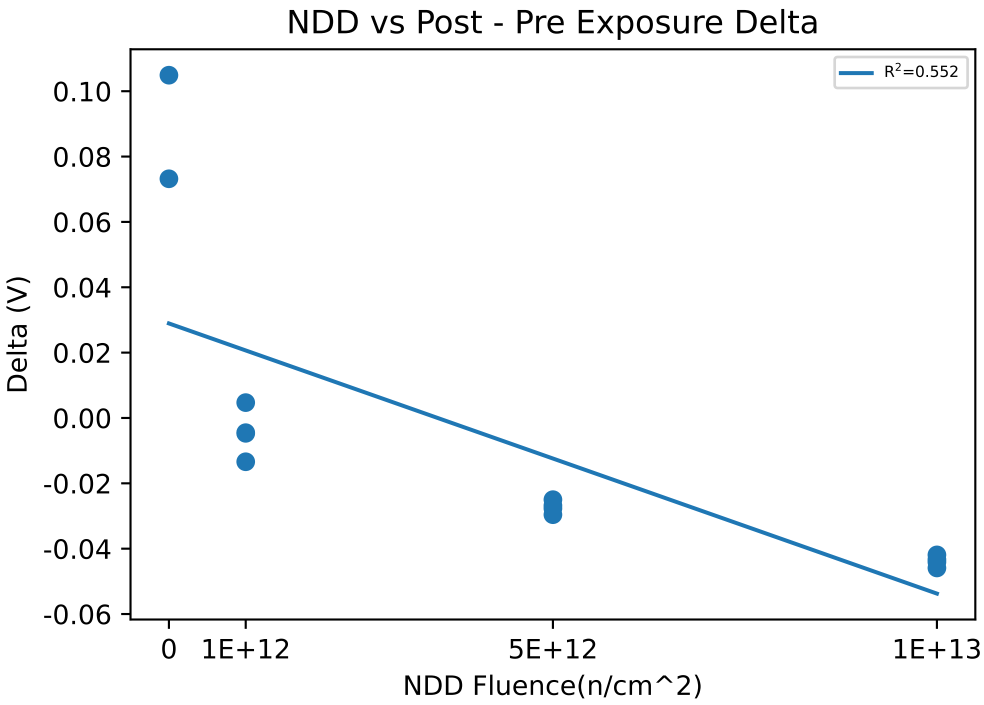
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	5.0025	4.9989	-0.0036
2	0	Correlation	5.0341	5.0265	-0.0076
30	1e+12	NDD unbiased	4.9957	4.9985	0.0028
31	1e+12	NDD unbiased	5.0033	4.995	-0.0083
32	1e+12	NDD unbiased	5.0144	5.0118	-0.0026
33	1e+12	NDD unbiased	5.0184	5.0158	-0.0026
44	5e+12	NDD unbiased	5.0118	4.9922	-0.0196
45	5e+12	NDD unbiased	4.9987	5.0055	0.0068
46	5e+12	NDD unbiased	4.9989	4.9786	-0.0203
47	5e+12	NDD unbiased	5.02	5.0038	-0.0162
50	1e+13	NDD unbiased	5.0247	4.9926	-0.0321
51	1e+13	NDD unbiased	4.9953	4.9624	-0.0329
52	1e+13	NDD unbiased	5.0097	4.9815	-0.0282
53	1e+13	NDD unbiased	5.0035	4.9678	-0.0357

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.0025	5.0183	5.0341	0.022345	4.9989	5.0127	5.0265	0.019516	-0.0076	-0.0056	-0.0036	0.0028284
1e+12	4.9957	5.008	5.0184	0.010368	4.995	5.0053	5.0158	0.01008	-0.0083	-0.002675	0.0028	0.0045324
5e+12	4.9987	5.0073	5.02	0.010425	4.9786	4.995	5.0055	0.012443	-0.0203	-0.012325	0.0068	0.012875
1e+13	4.9953	5.0083	5.0247	0.012423	4.9624	4.9761	4.9926	0.013638	-0.0357	-0.032225	-0.0282	0.0030956

Device Test: 61.12 V_BP7L(_V_BP7L IIM 500kHz VIN_12V)





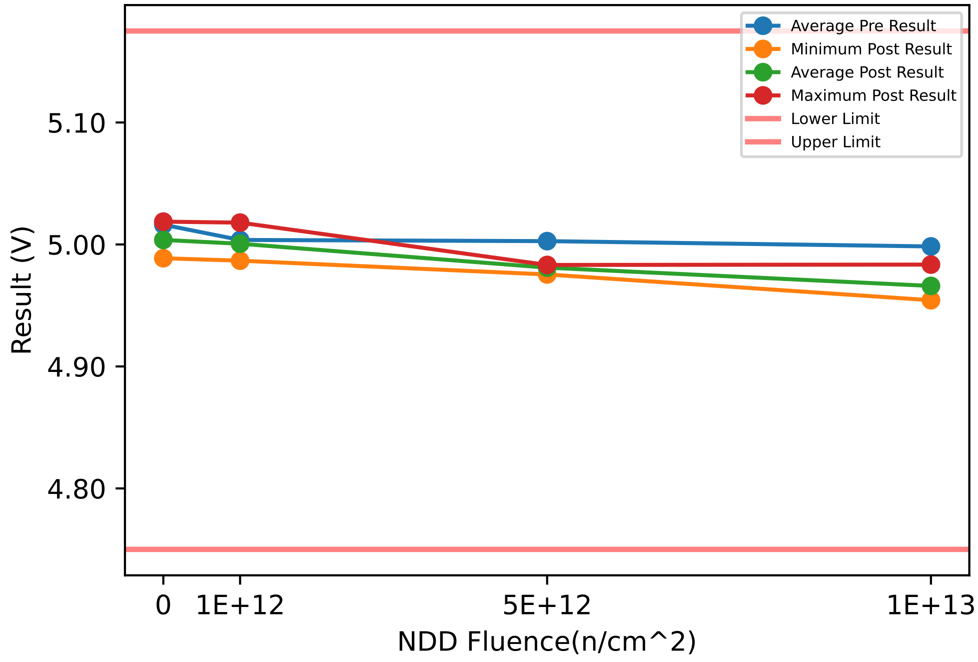
Test Results (Lower Limit = 6.65, Upper Limit = 7.35 (V))

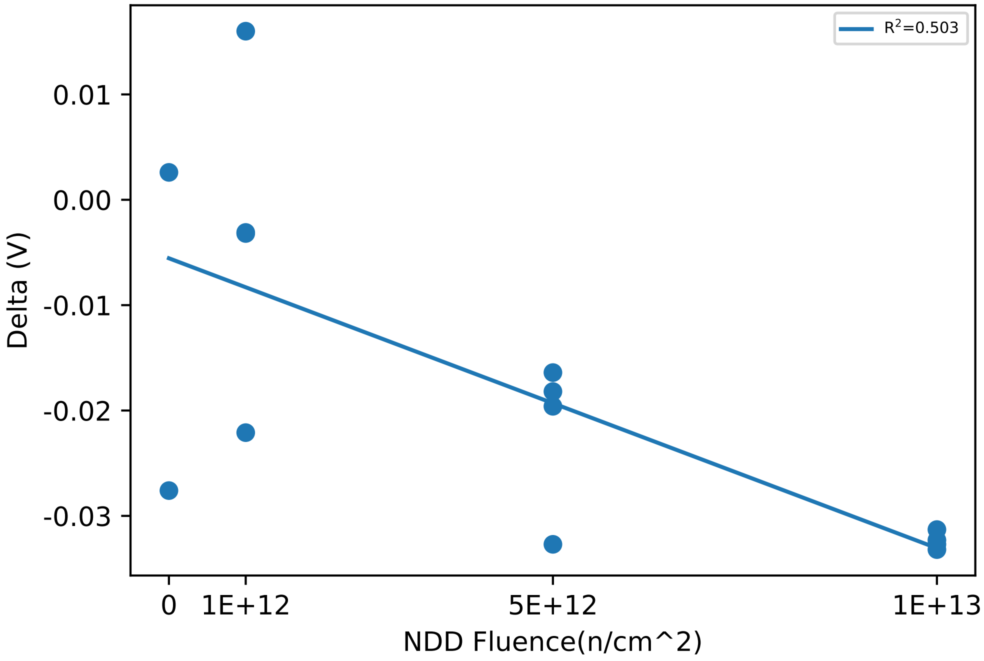
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	7.0025	7.0757	0.0732
2	0	Correlation	6.9954	7.1003	0.1049
30	1e+12	NDD unbiased	7.0307	7.0354	0.0047
31	1e+12	NDD unbiased	7.0397	7.0263	-0.0134
32	1e+12	NDD unbiased	6.994	6.9893	-0.0047
33	1e+12	NDD unbiased	7.0113	7.0068	-0.0045
44	5e+12	NDD unbiased	7.0495	7.0245	-0.025
45	5e+12	NDD unbiased	7.0396	7.01	-0.0296
46	5e+12	NDD unbiased	7.0928	7.066	-0.0268
47	5e+12	NDD unbiased	7.0378	7.0101	-0.0277
50	1e+13	NDD unbiased	6.9576	6.9157	-0.0419
51	1e+13	NDD unbiased	6.9593	6.9152	-0.0441
52	1e+13	NDD unbiased	6.9595	6.9162	-0.0433
53	1e+13	NDD unbiased	7.0085	6.9626	-0.0459

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	6.9954	6.999	7.0025	0.0050205	7.0757	7.088	7.1003	0.017395	0.0732	0.08905	0.1049	0.022415
1e+12	6.994	7.0189	7.0397	0.02041	6.9893	7.0145	7.0354	0.020578	-0.0134	-0.004475	0.0047	0.0073912
5e+12	7.0378	7.0549	7.0928	0.025769	7.01	7.0276	7.066	0.026459	-0.0296	-0.027275	-0.025	0.0019138
1e+13	6.9576	6.9712	7.0085	0.024865	6.9152	6.9274	6.9626	0.023454	-0.0459	-0.0438	-0.0419	0.0016693

Device Test: 61.13 V_BP5L(_V_BP5L IIM 500kHz VIN_12V)


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

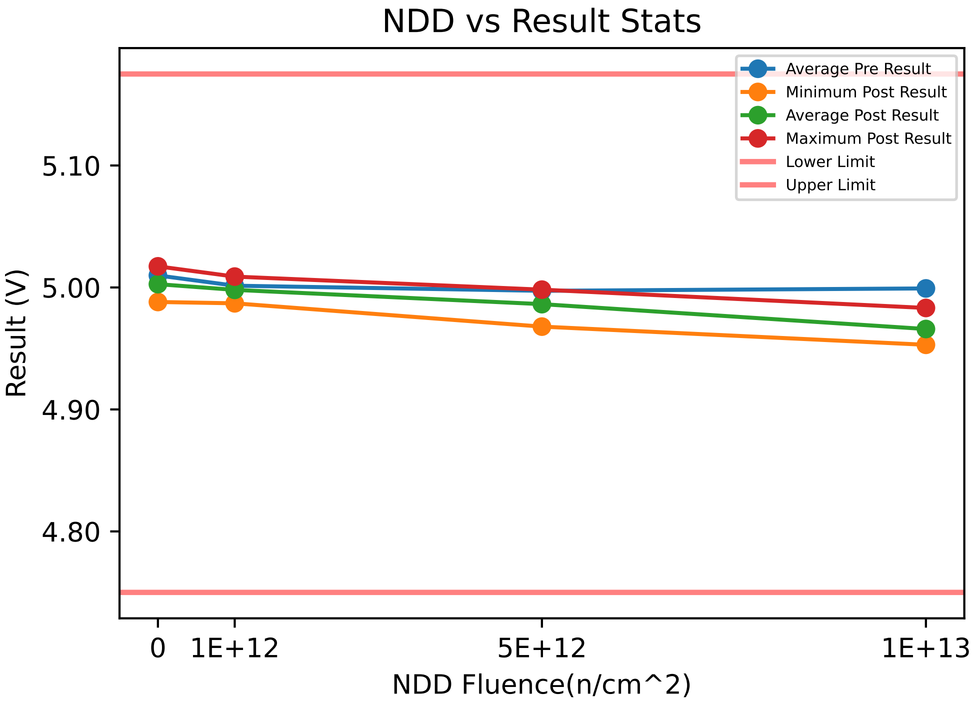
Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

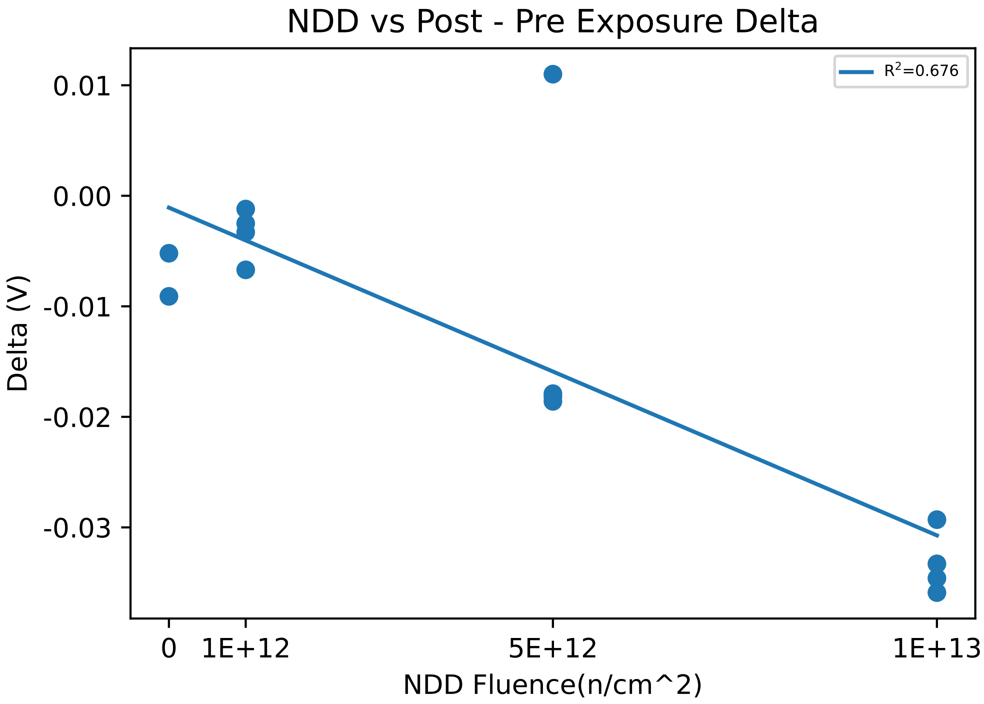
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	5.0163	4.9887	-0.0276
2	0	Correlation	5.0161	5.0187	0.0026
30	1e+12	NDD unbiased	5.0214	4.9993	-0.0221
31	1e+12	NDD unbiased	5.0019	5.0179	0.016
32	1e+12	NDD unbiased	5.0017	4.9985	-0.0032
33	1e+12	NDD unbiased	4.9898	4.9867	-0.0031
44	5e+12	NDD unbiased	4.9918	4.9754	-0.0164
45	5e+12	NDD unbiased	5.0159	4.9832	-0.0327
46	5e+12	NDD unbiased	5.0005	4.9823	-0.0182
47	5e+12	NDD unbiased	5.0027	4.9831	-0.0196
50	1e+13	NDD unbiased	4.9866	4.9543	-0.0323
51	1e+13	NDD unbiased	4.9986	4.9659	-0.0327
52	1e+13	NDD unbiased	5.0148	4.9835	-0.0313
53	1e+13	NDD unbiased	4.9935	4.9603	-0.0332

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.0161	5.0162	5.0163	0.00014142	4.9887	5.0037	5.0187	0.021213	-0.0276	-0.0125	0.0026	0.021355
1e+12	4.9898	5.0037	5.0214	0.013086	4.9867	5.0006	5.0179	0.012892	-0.0221	-0.0031	0.016	0.015554
5e+12	4.9918	5.0027	5.0159	0.0099647	4.9754	4.981	4.9832	0.003755	-0.0327	-0.021725	-0.0164	0.007433
1e+13	4.9866	4.9984	5.0148	0.012003	4.9543	4.966	4.9835	0.012592	-0.0332	-0.032375	-0.0313	0.00080571

Device Test: 61.14 V_BP5H(_V_BP5H IIM 500kHz VIN_12V)





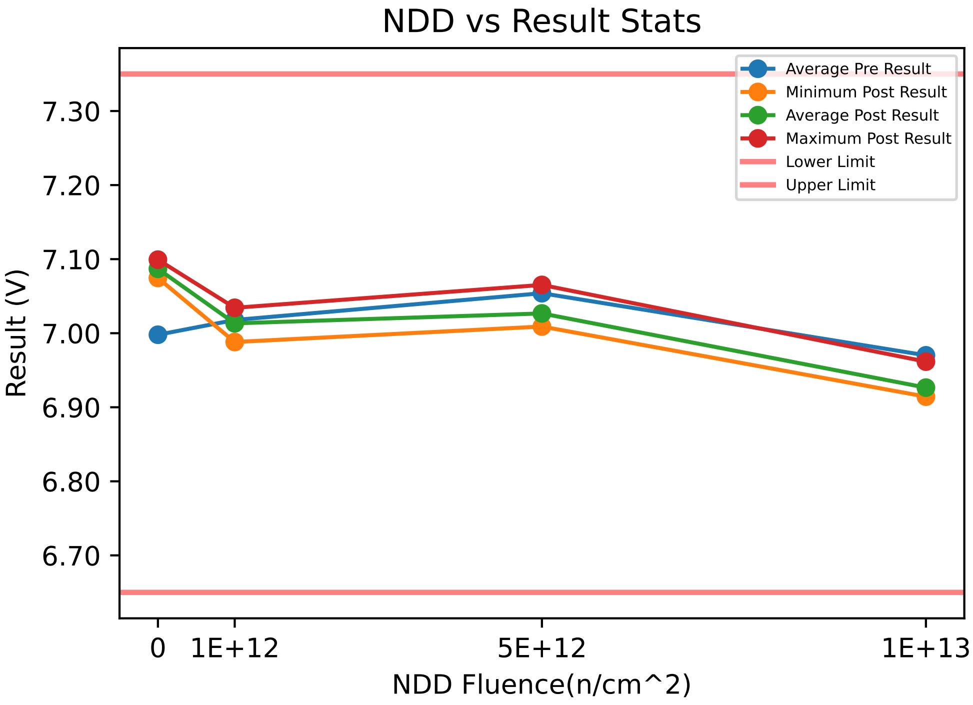
Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

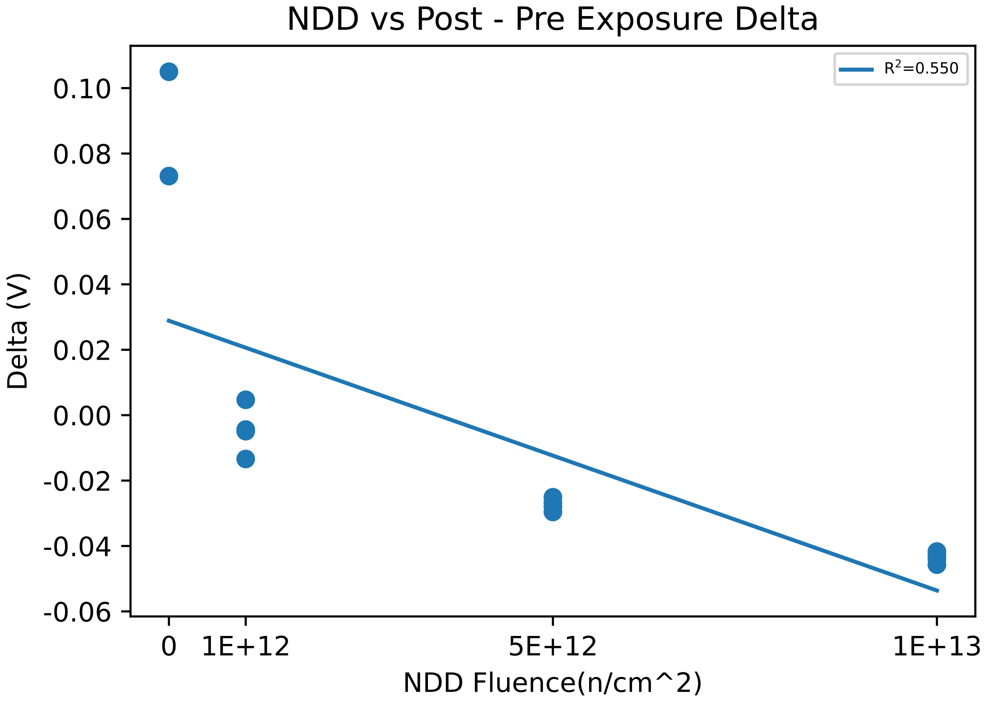
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	4.9972	4.9881	-0.0091
2	0	Correlation	5.0225	5.0173	-0.0052
30	1e+12	NDD unbiased	4.9904	4.9892	-0.0012
31	1e+12	NDD unbiased	4.9937	4.987	-0.0067
32	1e+12	NDD unbiased	5.0122	5.0089	-0.0033
33	1e+12	NDD unbiased	5.0095	5.007	-0.0025
44	5e+12	NDD unbiased	4.9992	4.9813	-0.0179
45	5e+12	NDD unbiased	4.9872	4.9982	0.011
46	5e+12	NDD unbiased	4.9865	4.9679	-0.0186
47	5e+12	NDD unbiased	5.0161	4.9979	-0.0182
50	1e+13	NDD unbiased	5.0165	4.9832	-0.0333
51	1e+13	NDD unbiased	4.9889	4.953	-0.0359
52	1e+13	NDD unbiased	5.0005	4.9712	-0.0293
53	1e+13	NDD unbiased	4.9909	4.9563	-0.0346

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.9972	5.0099	5.0225	0.01789	4.9881	5.0027	5.0173	0.020648	-0.0091	-0.00715	-0.0052	0.0027577
1e+12	4.9904	5.0015	5.0122	0.010993	4.987	4.998	5.0089	0.011522	-0.0067	-0.003425	-0.0012	0.0023486
5e+12	4.9865	4.9973	5.0161	0.013853	4.9679	4.9863	4.9982	0.014603	-0.0186	-0.010925	0.011	0.014619
1e+13	4.9889	4.9992	5.0165	0.012596	4.953	4.9659	4.9832	0.013976	-0.0359	-0.033275	-0.0293	0.0028547

Device Test: 61.15 V_BP7L(_V_BP7L IIM 1MHz VIN_12V)


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

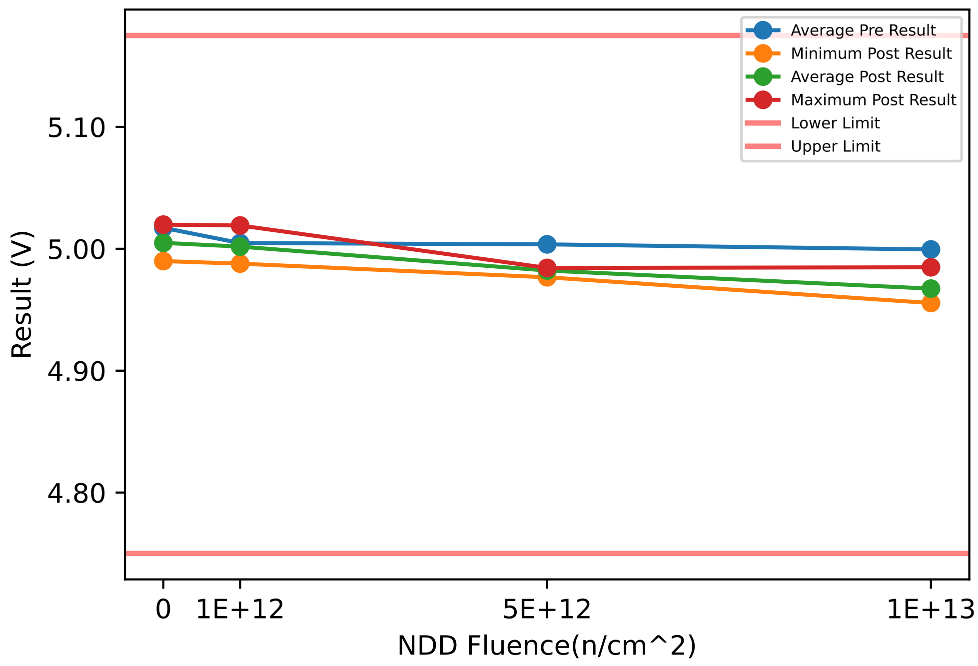
Test Results (Lower Limit = 6.65, Upper Limit = 7.35 (V))

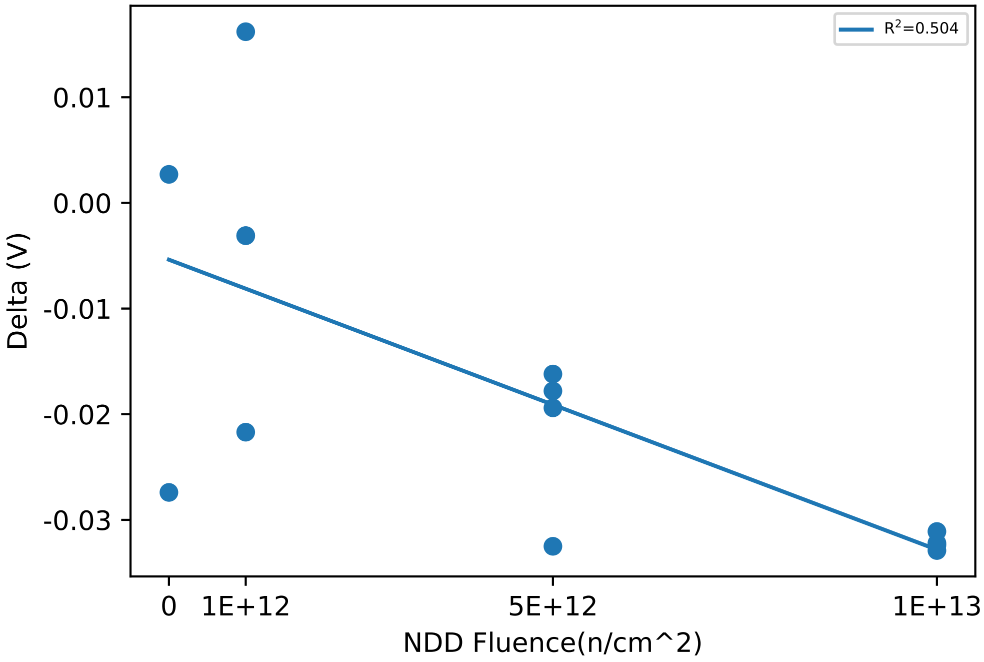
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	7.0015	7.0746	0.0731
2	0	Correlation	6.9943	7.0993	0.105
30	1e+12	NDD unbiased	7.0296	7.0343	0.0047
31	1e+12	NDD unbiased	7.0386	7.0252	-0.0134
32	1e+12	NDD unbiased	6.993	6.9881	-0.0049
33	1e+12	NDD unbiased	7.0101	7.0057	-0.0044
44	5e+12	NDD unbiased	7.0485	7.0234	-0.0251
45	5e+12	NDD unbiased	7.0387	7.0091	-0.0296
46	5e+12	NDD unbiased	7.0919	7.0652	-0.0267
47	5e+12	NDD unbiased	7.0369	7.009	-0.0279
50	1e+13	NDD unbiased	6.9564	6.9147	-0.0417
51	1e+13	NDD unbiased	6.9584	6.9143	-0.0441
52	1e+13	NDD unbiased	6.9584	6.9154	-0.043
53	1e+13	NDD unbiased	7.0073	6.9616	-0.0457

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	6.9943	6.9979	7.0015	0.0050912	7.0746	7.0869	7.0993	0.017466	0.0731	0.08905	0.105	0.022557
1e+12	6.993	7.0178	7.0386	0.020381	6.9881	7.0133	7.0343	0.020619	-0.0134	-0.0045	0.0047	0.0073941
5e+12	7.0369	7.054	7.0919	0.025776	7.009	7.0267	7.0652	0.026559	-0.0296	-0.027325	-0.0251	0.0019015
1e+13	6.9564	6.9701	7.0073	0.024801	6.9143	6.9265	6.9616	0.023404	-0.0457	-0.043625	-0.0417	0.0016958

Device Test: 61.16 V_BP5L(_V_BP5L IIM 1MHz VIN_12V)





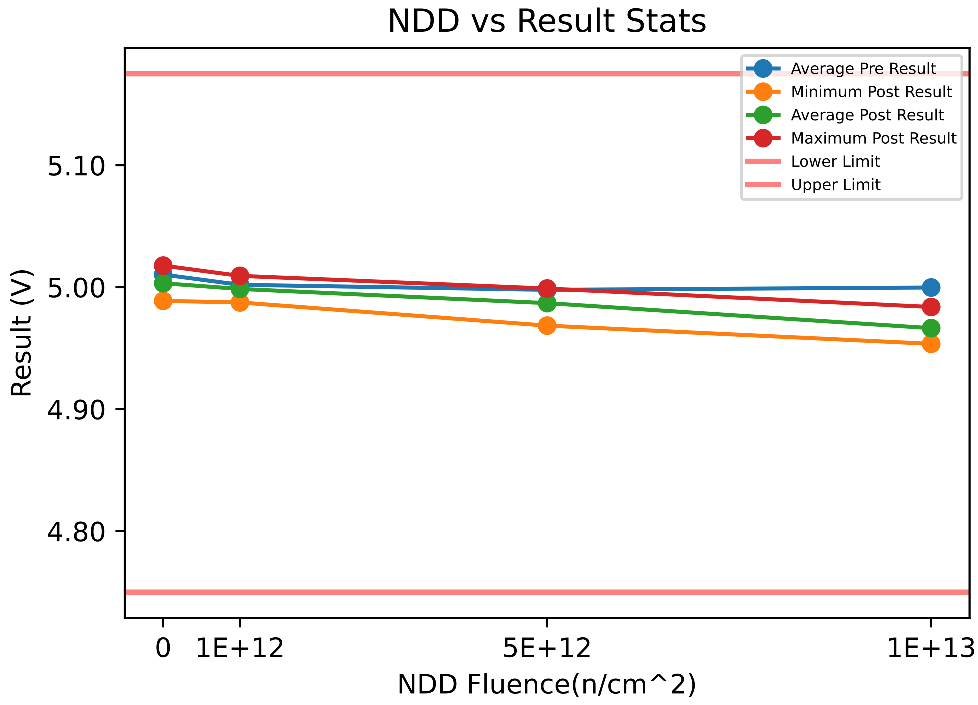
Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

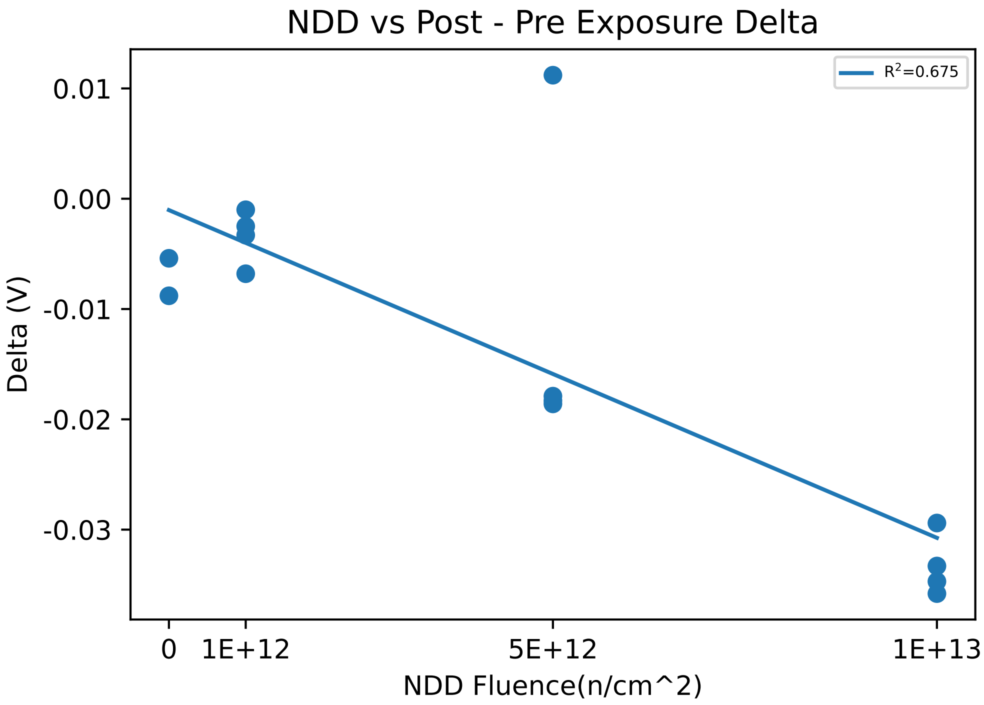
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	5.0173	4.9899	-0.0274
2	0	Correlation	5.0171	5.0198	0.0027
30	1e+12	NDD unbiased	5.0223	5.0006	-0.0217
31	1e+12	NDD unbiased	5.0029	5.0191	0.0162
32	1e+12	NDD unbiased	5.0027	4.9996	-0.0031
33	1e+12	NDD unbiased	4.9909	4.9878	-0.0031
44	5e+12	NDD unbiased	4.9928	4.9766	-0.0162
45	5e+12	NDD unbiased	5.0168	4.9843	-0.0325
46	5e+12	NDD unbiased	5.0014	4.9836	-0.0178
47	5e+12	NDD unbiased	5.0035	4.9841	-0.0194
50	1e+13	NDD unbiased	4.9877	4.9555	-0.0322
51	1e+13	NDD unbiased	4.9997	4.9673	-0.0324
52	1e+13	NDD unbiased	5.0159	4.9848	-0.0311
53	1e+13	NDD unbiased	4.9945	4.9616	-0.0329

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.0171	5.0172	5.0173	0.00014142	4.9899	5.0048	5.0198	0.021142	-0.0274	-0.01235	0.0027	0.021284
1e+12	4.9909	5.0047	5.0223	0.013006	4.9878	5.0018	5.0191	0.01293	-0.0217	-0.002925	0.0162	0.015474
5e+12	4.9928	5.0036	5.0168	0.0099285	4.9766	4.9821	4.9843	0.0037117	-0.0325	-0.021475	-0.0162	0.0074652
1e+13	4.9877	4.9995	5.0159	0.012017	4.9555	4.9673	4.9848	0.012622	-0.0329	-0.03215	-0.0311	0.00075939

Device Test: 61.17 V_BP5H(_V_BP5H IIM 1MHz VIN_12V)





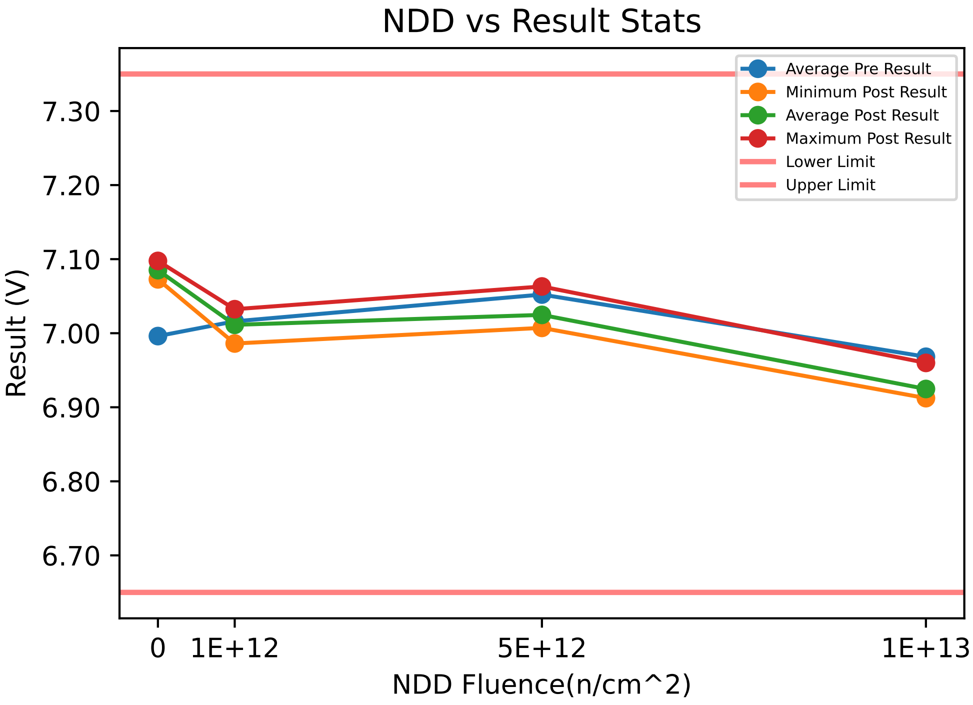
Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

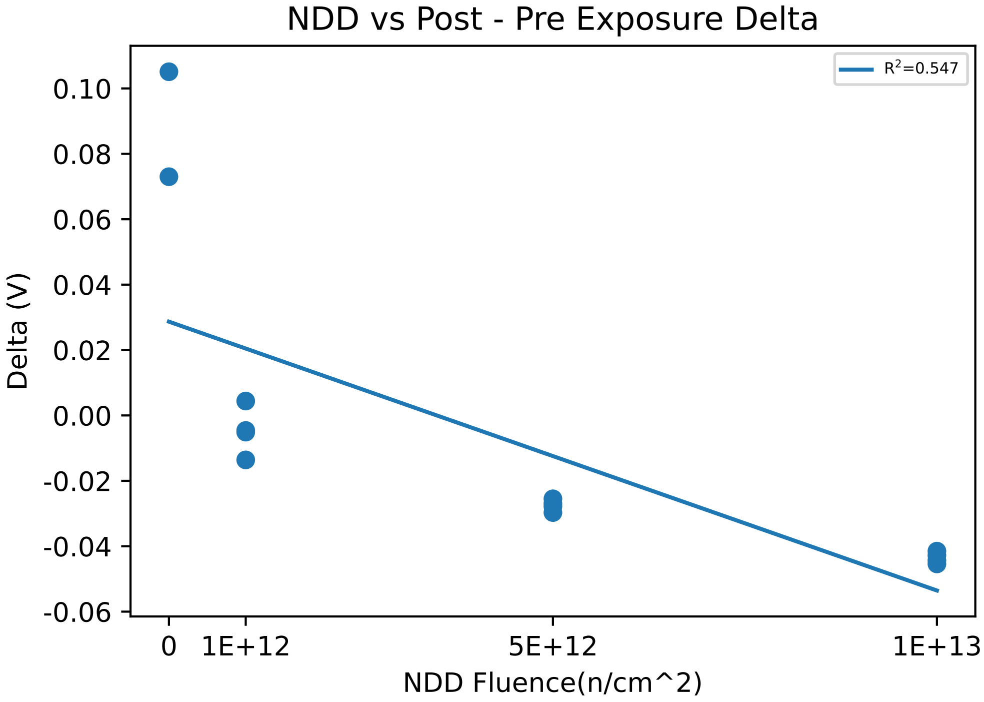
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	4.9976	4.9888	-0.0088
2	0	Correlation	5.0231	5.0177	-0.0054
30	1e+12	NDD unbiased	4.9909	4.9899	-0.001
31	1e+12	NDD unbiased	4.9943	4.9875	-0.0068
32	1e+12	NDD unbiased	5.0126	5.0093	-0.0033
33	1e+12	NDD unbiased	5.0101	5.0076	-0.0025
44	5e+12	NDD unbiased	4.9998	4.9819	-0.0179
45	5e+12	NDD unbiased	4.9877	4.9989	0.0112
46	5e+12	NDD unbiased	4.9871	4.9685	-0.0186
47	5e+12	NDD unbiased	5.0168	4.9985	-0.0183
50	1e+13	NDD unbiased	5.0171	4.9838	-0.0333
51	1e+13	NDD unbiased	4.9894	4.9536	-0.0358
52	1e+13	NDD unbiased	5.001	4.9716	-0.0294
53	1e+13	NDD unbiased	4.9915	4.9568	-0.0347

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.9976	5.0104	5.0231	0.018031	4.9888	5.0032	5.0177	0.020435	-0.0088	-0.0071	-0.0054	0.0024042
1e+12	4.9909	5.002	5.0126	0.010962	4.9875	4.9986	5.0093	0.011466	-0.0068	-0.0034	-0.001	0.002459
5e+12	4.9871	4.9978	5.0168	0.013922	4.9685	4.987	4.9989	0.01463	-0.0186	-0.0109	0.0112	0.014736
1e+13	4.9894	4.9998	5.0171	0.01262	4.9536	4.9665	4.9838	0.013974	-0.0358	-0.0333	-0.0294	0.002794

Device Test: 61.18 V_BP7L(_V_BP7L IIM 2MHz VIN_12V)


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

Test Results (Lower Limit = 6.65, Upper Limit = 7.35 (V))

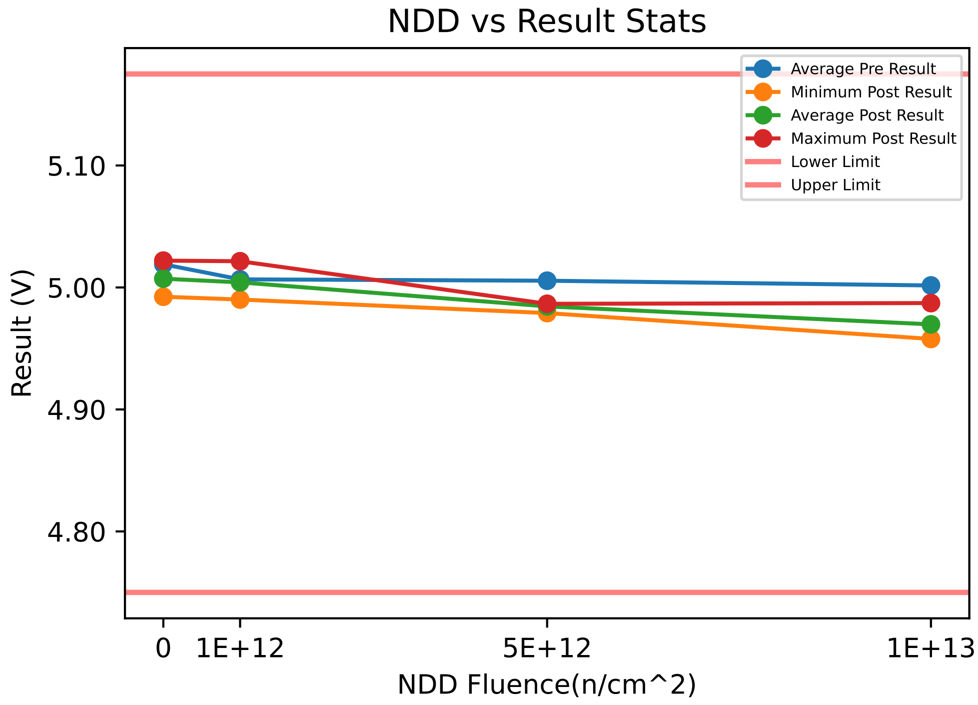
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	6.9997	7.0727	0.073
2	0	Correlation	6.9925	7.0976	0.1051
30	1e+12	NDD unbiased	7.028	7.0324	0.0044
31	1e+12	NDD unbiased	7.0369	7.0233	-0.0136
32	1e+12	NDD unbiased	6.9912	6.9861	-0.0051
33	1e+12	NDD unbiased	7.008	7.0034	-0.0046
44	5e+12	NDD unbiased	7.0468	7.0213	-0.0255
45	5e+12	NDD unbiased	7.037	7.0073	-0.0297
46	5e+12	NDD unbiased	7.09	7.0631	-0.0269
47	5e+12	NDD unbiased	7.035	7.0072	-0.0278
50	1e+13	NDD unbiased	6.9544	6.9129	-0.0415
51	1e+13	NDD unbiased	6.9566	6.9123	-0.0443
52	1e+13	NDD unbiased	6.9564	6.9136	-0.0428
53	1e+13	NDD unbiased	7.0053	6.9599	-0.0454

Test Statistics (V)

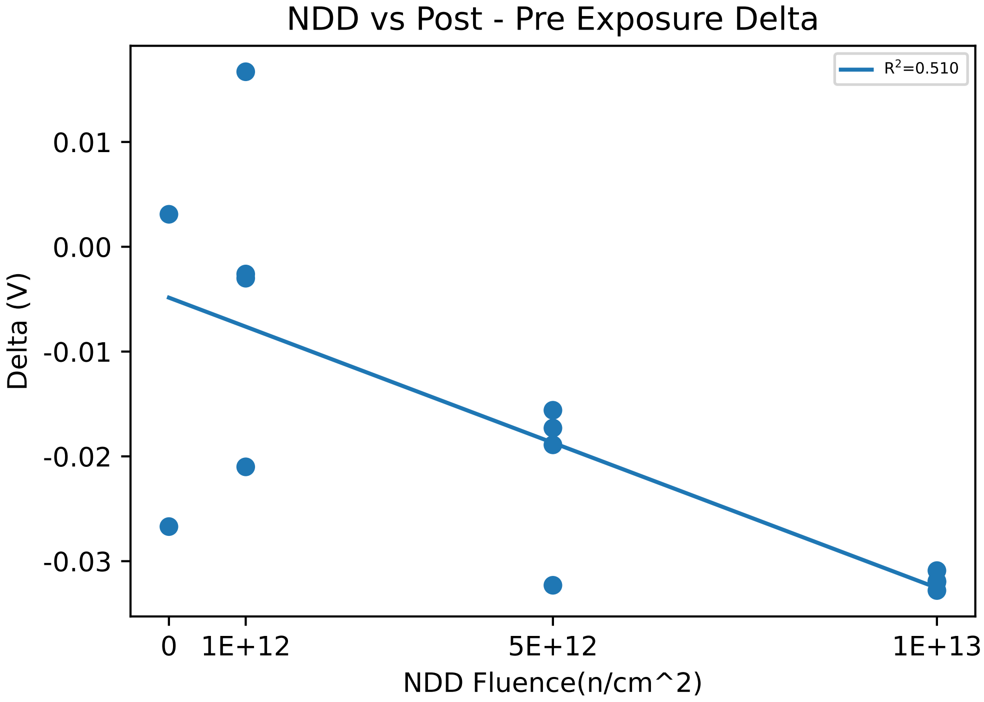
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	6.9925	6.9961	6.9997	0.0050912	7.0727	7.0852	7.0976	0.017607	0.073	0.08905	0.1051	0.022698
1e+12	6.9912	7.016	7.0369	0.020493	6.9861	7.0113	7.0324	0.02071	-0.0136	-0.004725	0.0044	0.0073527
5e+12	7.035	7.0522	7.09	0.025722	7.0072	7.0247	7.0631	0.026427	-0.0297	-0.027475	-0.0255	0.0017595
1e+13	6.9544	6.9682	7.0053	0.02477	6.9123	6.9247	6.9599	0.023489	-0.0454	-0.0435	-0.0415	0.0017068

Device Test: 61.19 V_BP5L(_V_BP5L IIM 2MHz VIN_12V)

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



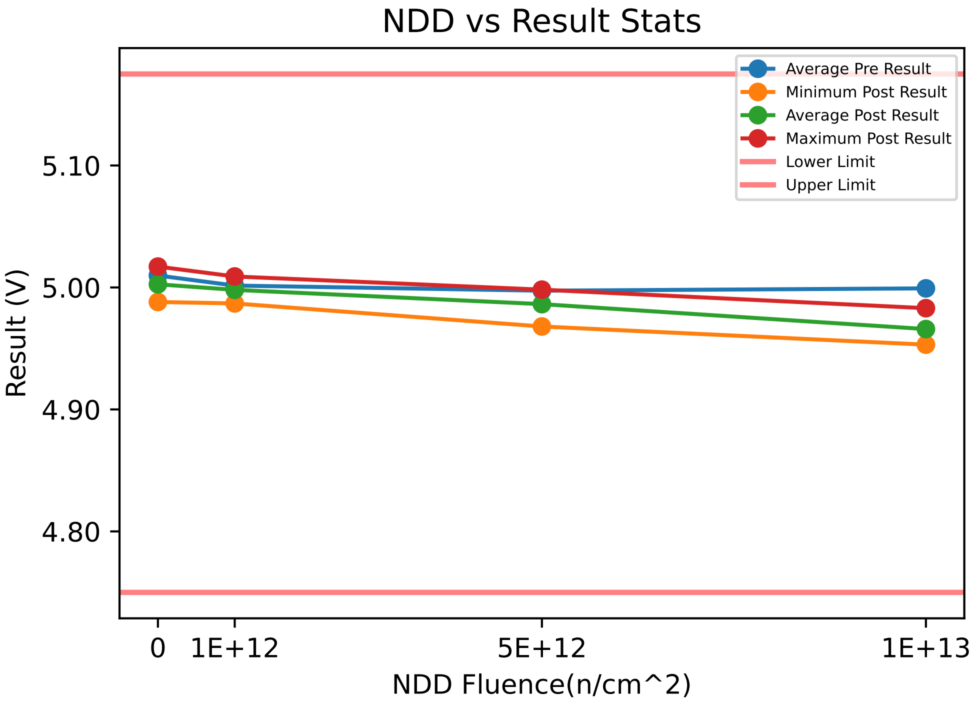
Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

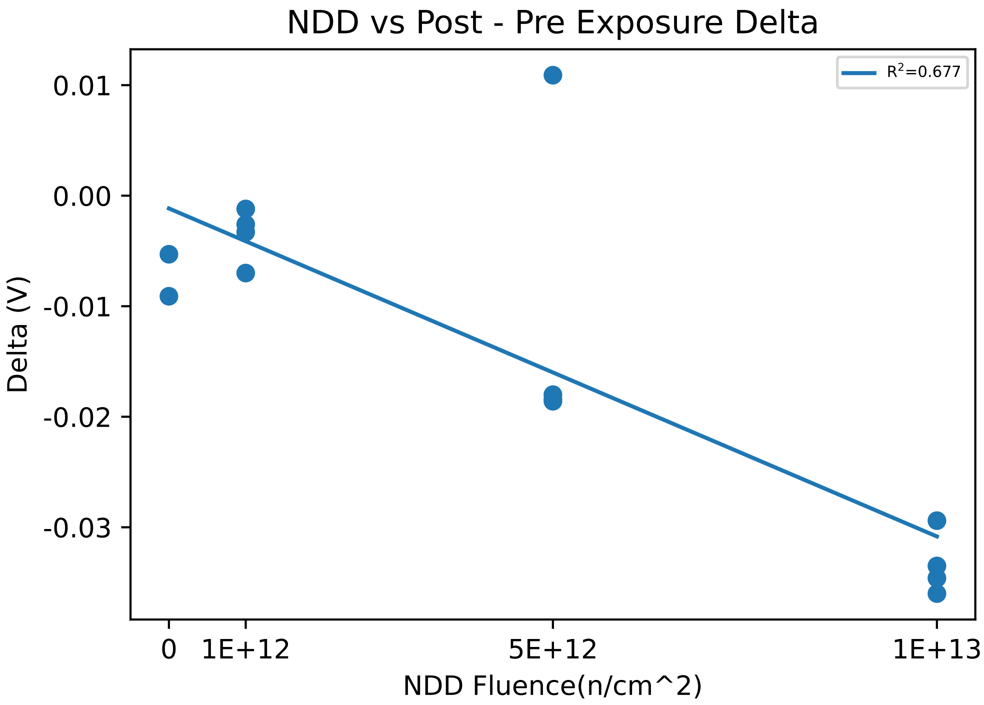
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	5.0191	4.9924	-0.0267
2	0	Correlation	5.0189	5.022	0.0031
30	1e+12	NDD unbiased	5.0241	5.0031	-0.021
31	1e+12	NDD unbiased	5.0048	5.0215	0.0167
32	1e+12	NDD unbiased	5.0046	5.002	-0.0026
33	1e+12	NDD unbiased	4.9931	4.9901	-0.003
44	5e+12	NDD unbiased	4.9946	4.979	-0.0156
45	5e+12	NDD unbiased	5.0189	4.9866	-0.0323
46	5e+12	NDD unbiased	5.0033	4.986	-0.0173
47	5e+12	NDD unbiased	5.0053	4.9864	-0.0189
50	1e+13	NDD unbiased	4.9898	4.9578	-0.032
51	1e+13	NDD unbiased	5.0019	4.97	-0.0319
52	1e+13	NDD unbiased	5.0181	4.9872	-0.0309
53	1e+13	NDD unbiased	4.9968	4.964	-0.0328

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.0189	5.019	5.0191	0.00014142	4.9924	5.0072	5.022	0.02093	-0.0267	-0.0118	0.0031	0.021072
1e+12	4.9931	5.0067	5.0241	0.012855	4.9901	5.0042	5.0215	0.012963	-0.021	-0.002475	0.0167	0.015396
5e+12	4.9946	5.0055	5.0189	0.010054	4.979	4.9845	4.9866	0.0036751	-0.0323	-0.021025	-0.0156	0.0076365
1e+13	4.9898	5.0016	5.0181	0.012036	4.9578	4.9697	4.9872	0.012655	-0.0328	-0.0319	-0.0309	0.00077889

Device Test: 61.2 V_BP5H(_V_BP5H PWM 500kHz VIN_12V)





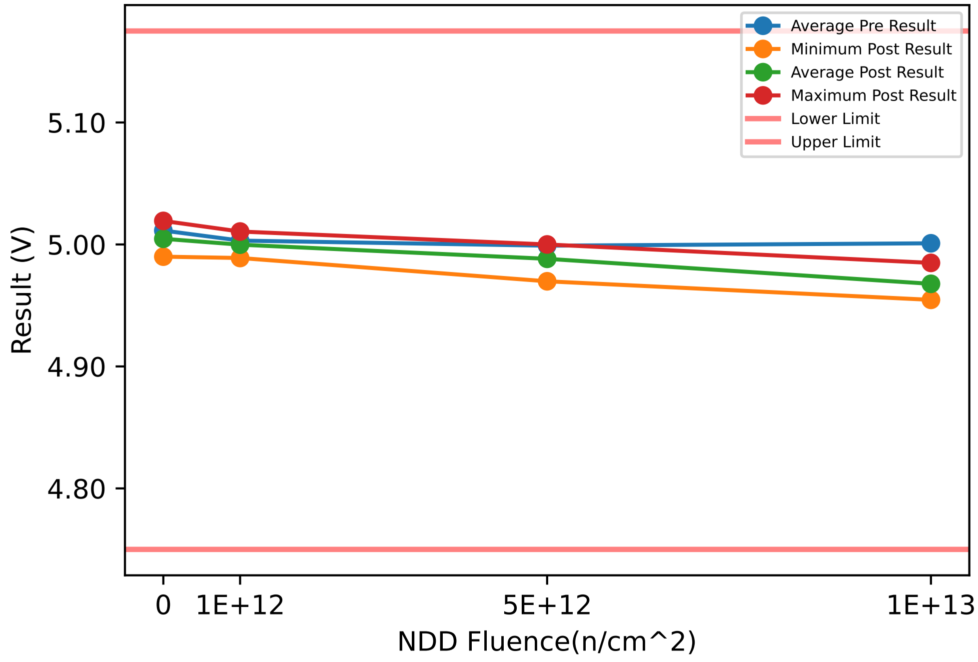
Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	4.9972	4.9881	-0.0091
2	0	Correlation	5.0224	5.0171	-0.0053
30	1e+12	NDD unbiased	4.9905	4.9893	-0.0012
31	1e+12	NDD unbiased	4.9939	4.9869	-0.007
32	1e+12	NDD unbiased	5.0123	5.009	-0.0033
33	1e+12	NDD unbiased	5.0095	5.0069	-0.0026
44	5e+12	NDD unbiased	4.9993	4.9813	-0.018
45	5e+12	NDD unbiased	4.9873	4.9982	0.0109
46	5e+12	NDD unbiased	4.9866	4.968	-0.0186
47	5e+12	NDD unbiased	5.0162	4.9978	-0.0184
50	1e+13	NDD unbiased	5.0165	4.983	-0.0335
51	1e+13	NDD unbiased	4.9891	4.9531	-0.036
52	1e+13	NDD unbiased	5.0005	4.9711	-0.0294
53	1e+13	NDD unbiased	4.9909	4.9563	-0.0346

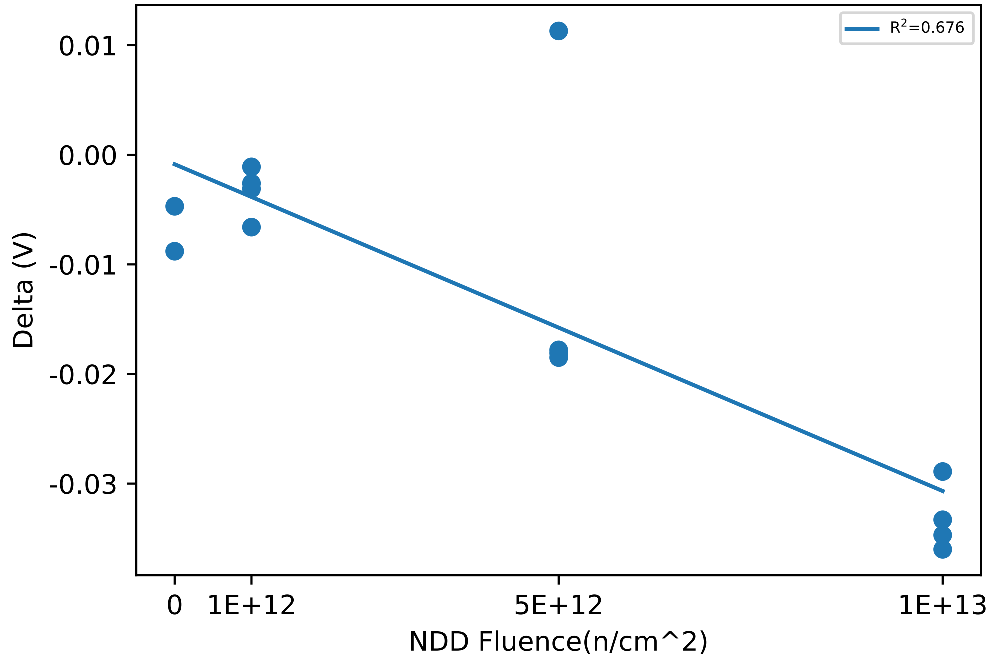
Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.9972	5.0098	5.0224	0.017819	4.9881	5.0026	5.0171	0.020506	-0.0091	-0.0072	-0.0053	0.002687
1e+12	4.9905	5.0015	5.0123	0.010945	4.9869	4.998	5.009	0.011534	-0.007	-0.003525	-0.0012	0.0024757
5e+12	4.9866	4.9973	5.0162	0.013853	4.968	4.9863	4.9982	0.014534	-0.0186	-0.011025	0.0109	0.014619
1e+13	4.9891	4.9992	5.0165	0.012542	4.9531	4.9659	4.983	0.01385	-0.036	-0.033375	-0.0294	0.0028406

Device Test: 61.20 V_BP5H(_V_BP5H IIM 2MHz VIN_12V)



NDD vs Result Stats



NDD vs Post - Pre Exposure Delta

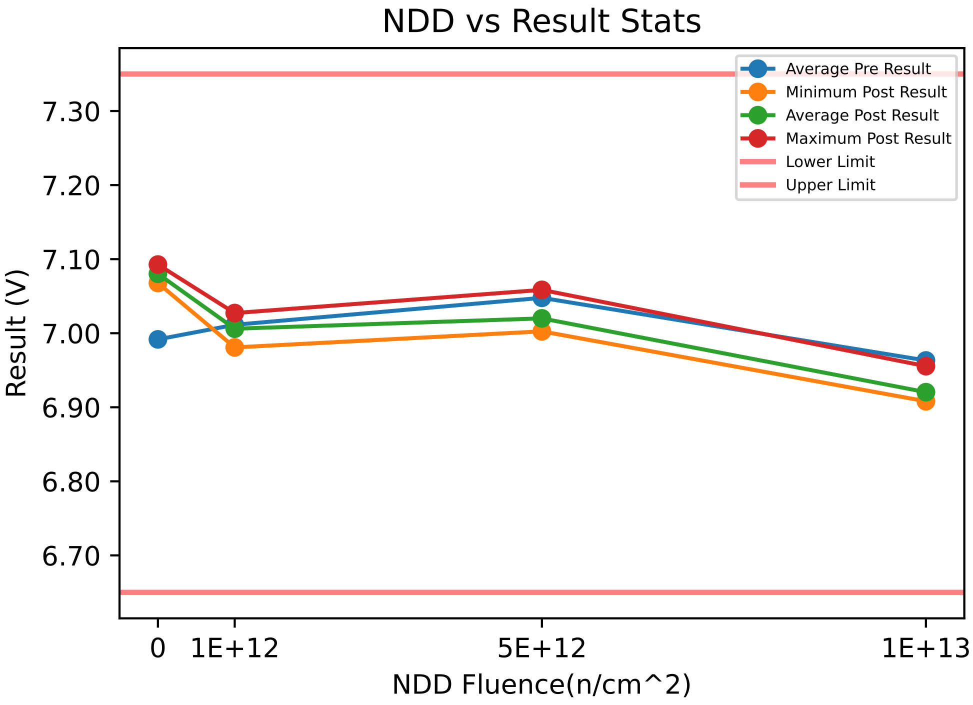
Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

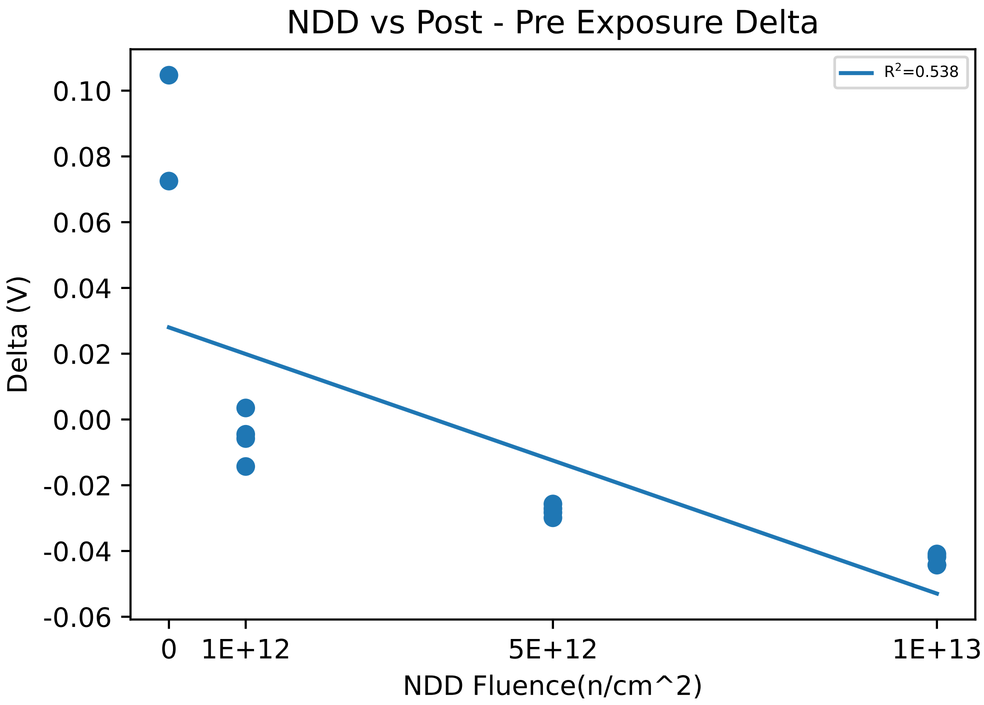
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	4.9988	4.99	-0.0088
2	0	Correlation	5.024	5.0193	-0.0047
30	1e+12	NDD unbiased	4.9922	4.9911	-0.0011
31	1e+12	NDD unbiased	4.9955	4.9889	-0.0066
32	1e+12	NDD unbiased	5.0137	5.0106	-0.0031
33	1e+12	NDD unbiased	5.0113	5.0087	-0.0026
44	5e+12	NDD unbiased	5.0012	4.9834	-0.0178
45	5e+12	NDD unbiased	4.9887	5	0.0113
46	5e+12	NDD unbiased	4.9883	4.9698	-0.0185
47	5e+12	NDD unbiased	5.0178	4.9997	-0.0181
50	1e+13	NDD unbiased	5.0182	4.9849	-0.0333
51	1e+13	NDD unbiased	4.9906	4.9546	-0.036
52	1e+13	NDD unbiased	5.0021	4.9732	-0.0289
53	1e+13	NDD unbiased	4.9929	4.9582	-0.0347

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.9988	5.0114	5.024	0.017819	4.99	5.0046	5.0193	0.020718	-0.0088	-0.00675	-0.0047	0.0028991
1e+12	4.9922	5.0032	5.0137	0.010896	4.9889	4.9998	5.0106	0.011407	-0.0066	-0.00335	-0.0011	0.0023274
5e+12	4.9883	4.999	5.0178	0.013891	4.9698	4.9882	5	0.014527	-0.0185	-0.010775	0.0113	0.014719
1e+13	4.9906	5.0009	5.0182	0.012527	4.9546	4.9677	4.9849	0.013999	-0.036	-0.033225	-0.0289	0.0030869

Device Test: 61.21 V_BP7L(_V_BP7L IIM 5MHz VIN_12V)





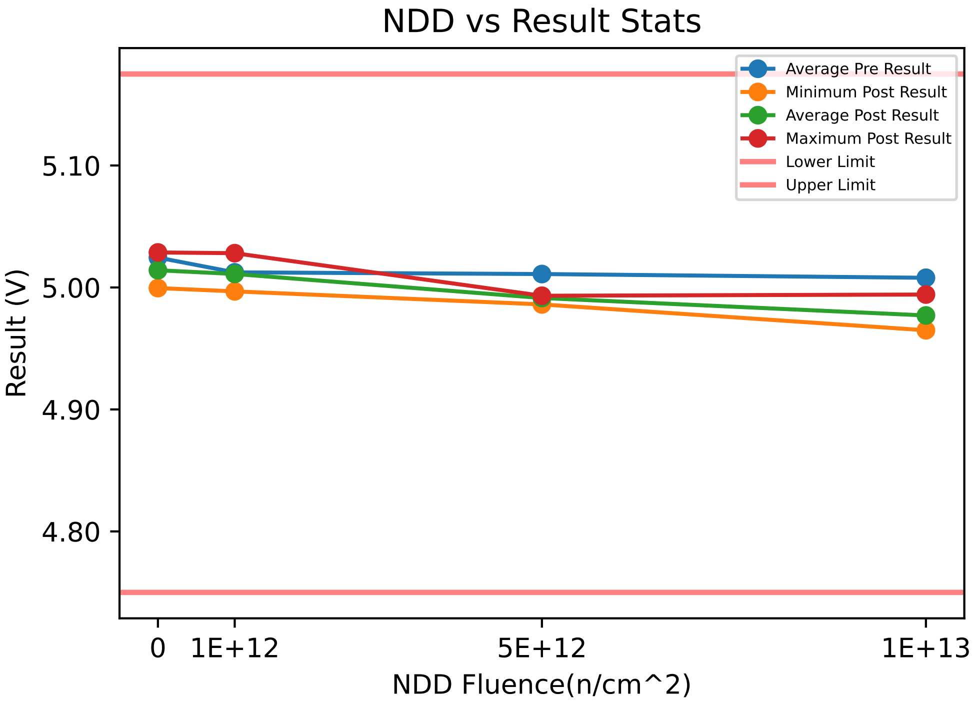
Test Results (Lower Limit = 6.65, Upper Limit = 7.35 (V))

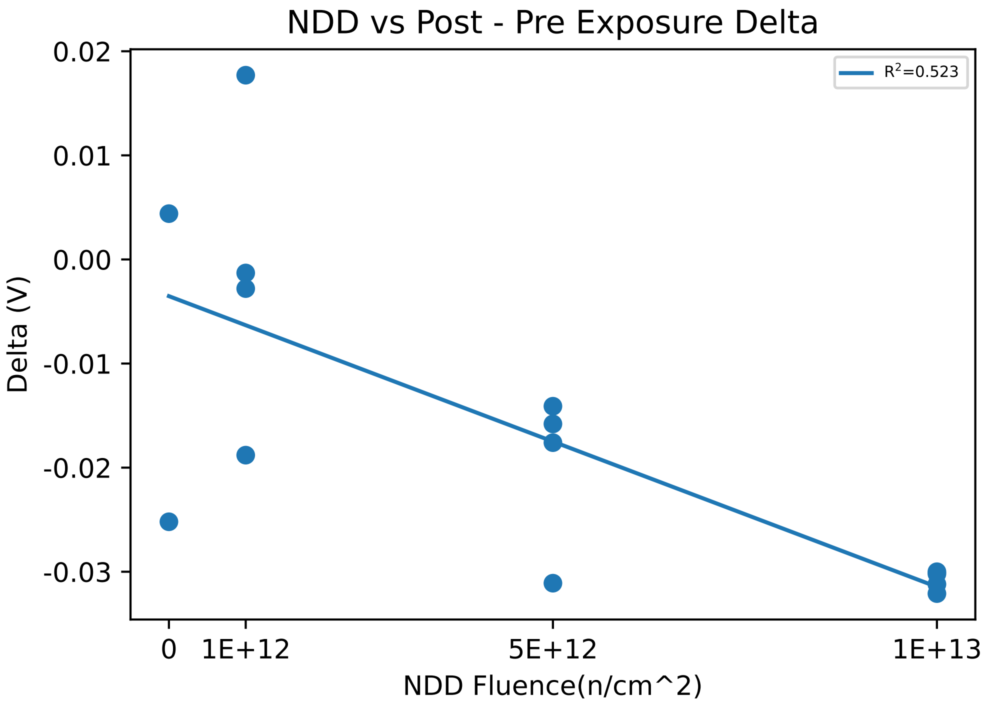
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	6.9953	7.0678	0.0725
2	0	Correlation	6.988	7.0927	0.1047
30	1e+12	NDD unbiased	7.0237	7.0272	0.0035
31	1e+12	NDD unbiased	7.0327	7.0184	-0.0143
32	1e+12	NDD unbiased	6.9866	6.9808	-0.0058
33	1e+12	NDD unbiased	7.0024	6.9979	-0.0045
44	5e+12	NDD unbiased	7.042	7.0163	-0.0257
45	5e+12	NDD unbiased	7.0326	7.0027	-0.0299
46	5e+12	NDD unbiased	7.0856	7.0585	-0.0271
47	5e+12	NDD unbiased	7.0308	7.0025	-0.0283
50	1e+13	NDD unbiased	6.9494	6.9085	-0.0409
51	1e+13	NDD unbiased	6.9523	6.9081	-0.0442
52	1e+13	NDD unbiased	6.9512	6.9094	-0.0418
53	1e+13	NDD unbiased	6.9998	6.9555	-0.0443

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	6.988	6.9916	6.9953	0.0051619	7.0678	7.0802	7.0927	0.017607	0.0725	0.0886	0.1047	0.022769
1e+12	6.9866	7.0114	7.0327	0.020825	6.9808	7.0061	7.0272	0.020847	-0.0143	-0.005275	0.0035	0.0072876
5e+12	7.0308	7.0478	7.0856	0.025707	7.0025	7.02	7.0585	0.026467	-0.0299	-0.02775	-0.0257	0.0017842
1e+13	6.9494	6.9632	6.9998	0.024446	6.9081	6.9204	6.9555	0.023423	-0.0443	-0.0428	-0.0409	0.0017146

Device Test: 61.22 V_BP5L(_V_BP5L IIM 5MHz VIN_12V)





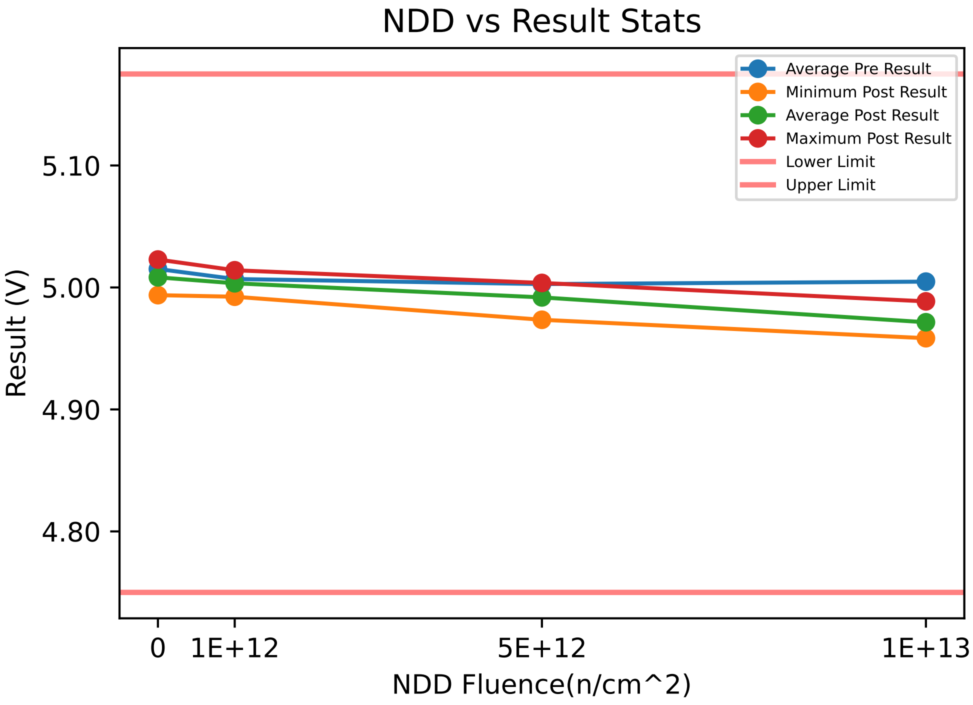
Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

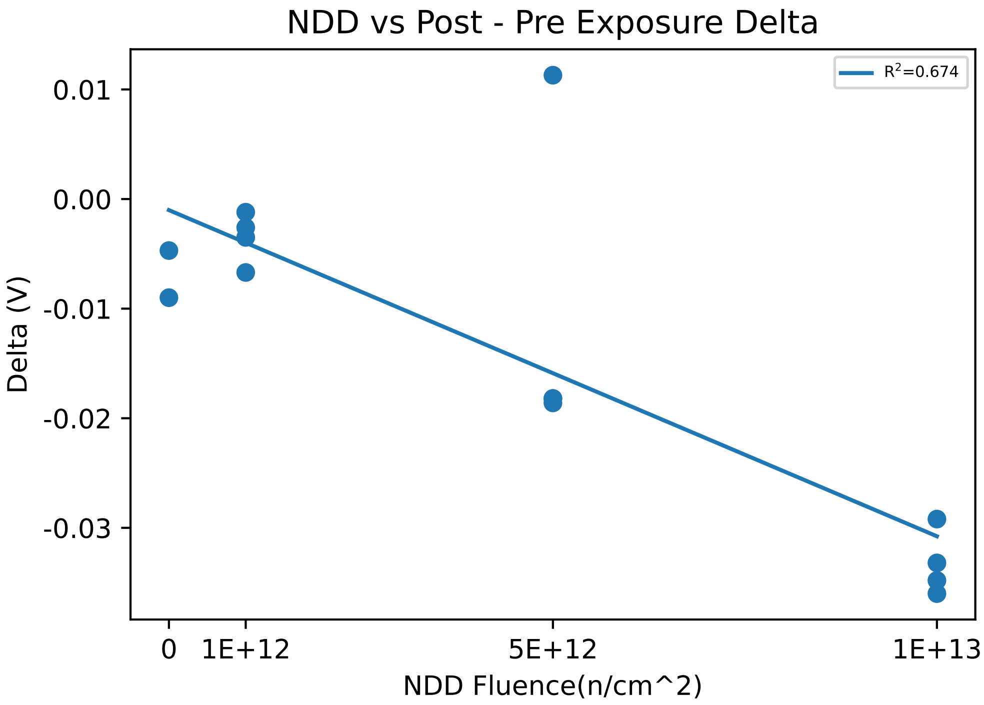
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	5.0247	4.9995	-0.0252
2	0	Correlation	5.0243	5.0287	0.0044
30	1e+12	NDD unbiased	5.0294	5.0106	-0.0188
31	1e+12	NDD unbiased	5.0104	5.0281	0.0177
32	1e+12	NDD unbiased	5.0101	5.0088	-0.0013
33	1e+12	NDD unbiased	4.9996	4.9968	-0.0028
44	5e+12	NDD unbiased	5.0002	4.9861	-0.0141
45	5e+12	NDD unbiased	5.0243	4.9932	-0.0311
46	5e+12	NDD unbiased	5.0089	4.9931	-0.0158
47	5e+12	NDD unbiased	5.0106	4.993	-0.0176
50	1e+13	NDD unbiased	4.9961	4.9649	-0.0312
51	1e+13	NDD unbiased	5.008	4.978	-0.03
52	1e+13	NDD unbiased	5.0244	4.9942	-0.0302
53	1e+13	NDD unbiased	5.0032	4.9711	-0.0321

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.0243	5.0245	5.0247	0.00028284	4.9995	5.0141	5.0287	0.020648	-0.0252	-0.0104	0.0044	0.02093
1e+12	4.9996	5.0124	5.0294	0.012411	4.9968	5.0111	5.0281	0.012897	-0.0188	-0.0013	0.0177	0.014939
5e+12	5.0002	5.011	5.0243	0.0099683	4.9861	4.9914	4.9932	0.003501	-0.0311	-0.01965	-0.0141	0.007766
1e+13	4.9961	5.0079	5.0244	0.012022	4.9649	4.9771	4.9942	0.012623	-0.0321	-0.030875	-0.03	0.00097082

Device Test: 61.23 V_BP5H(_V_BP5H IIM 5MHz VIN_12V)


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

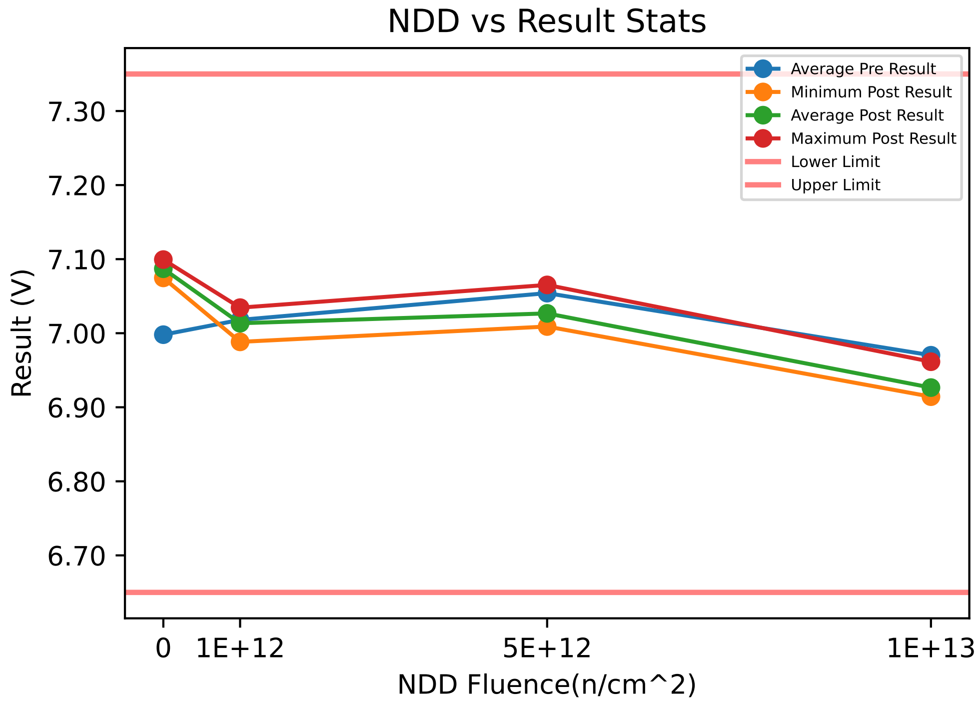
Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

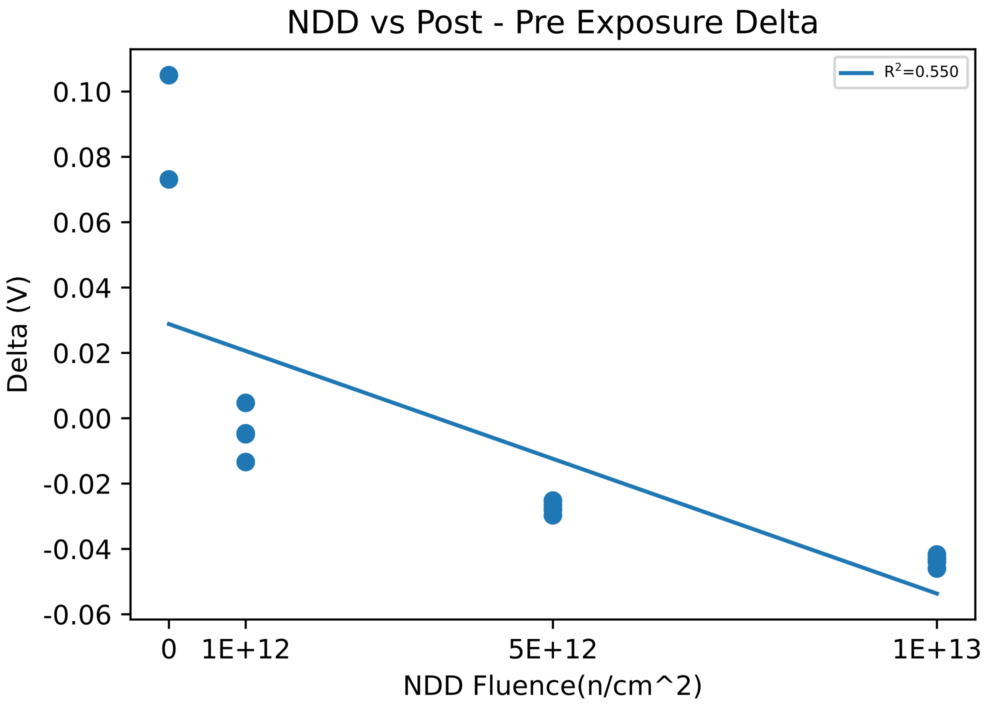
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	5.0027	4.9937	-0.009
2	0	Correlation	5.0276	5.0229	-0.0047
30	1e+12	NDD unbiased	4.9959	4.9947	-0.0012
31	1e+12	NDD unbiased	4.9991	4.9924	-0.0067
32	1e+12	NDD unbiased	5.0176	5.0141	-0.0035
33	1e+12	NDD unbiased	5.0151	5.0125	-0.0026
44	5e+12	NDD unbiased	5.005	4.9868	-0.0182
45	5e+12	NDD unbiased	4.9924	5.0037	0.0113
46	5e+12	NDD unbiased	4.9921	4.9735	-0.0186
47	5e+12	NDD unbiased	5.0216	5.0034	-0.0182
50	1e+13	NDD unbiased	5.0218	4.9886	-0.0332
51	1e+13	NDD unbiased	4.9944	4.9584	-0.036
52	1e+13	NDD unbiased	5.006	4.9768	-0.0292
53	1e+13	NDD unbiased	4.9969	4.9621	-0.0348

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.0027	5.0152	5.0276	0.017607	4.9937	5.0083	5.0229	0.020648	-0.009	-0.00685	-0.0047	0.0030406
1e+12	4.9959	5.0069	5.0176	0.011009	4.9924	5.0034	5.0141	0.01146	-0.0067	-0.0035	-0.0012	0.0023338
5e+12	4.9921	5.0028	5.0216	0.013916	4.9735	4.9918	5.0037	0.014561	-0.0186	-0.010925	0.0113	0.014818
1e+13	4.9944	5.0048	5.0218	0.012396	4.9584	4.9715	4.9886	0.01391	-0.036	-0.0333	-0.0292	0.0029642

Device Test: 61.3 V_BP7L(_V_BP7L PWM 1MHz VIN_12V)





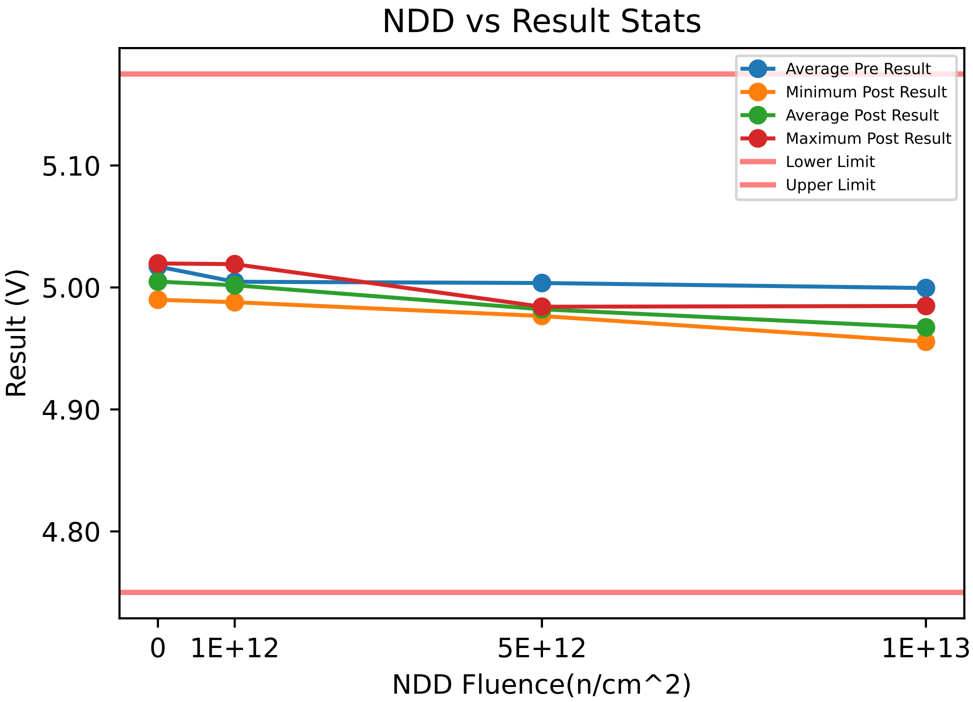
Test Results (Lower Limit = 6.65, Upper Limit = 7.35 (V))

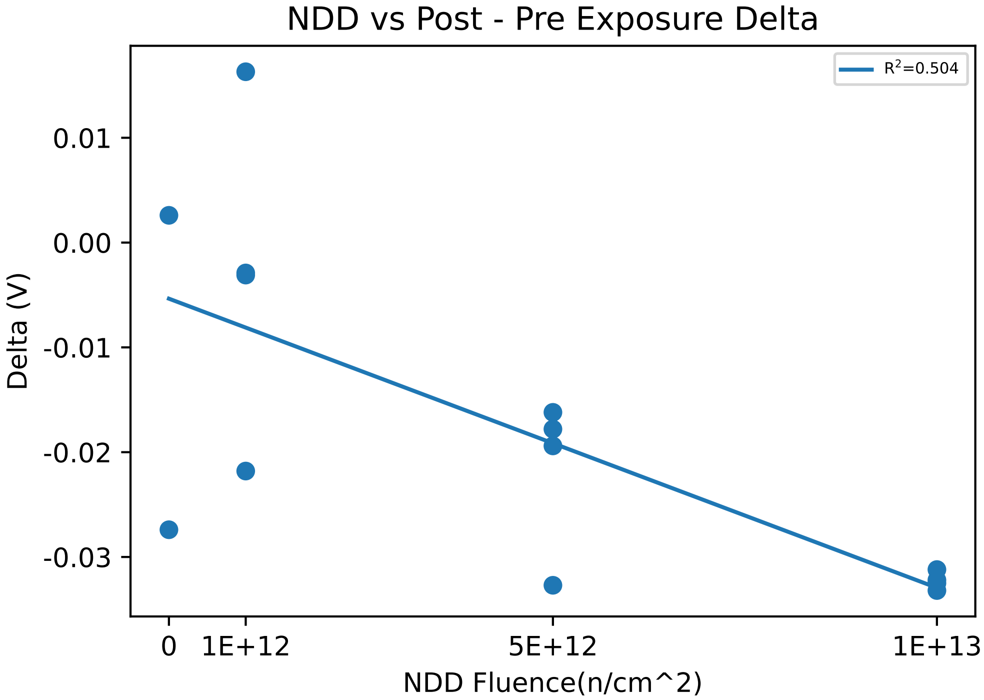
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	7.0016	7.0747	0.0731
2	0	Correlation	6.9944	7.0994	0.105
30	1e+12	NDD unbiased	7.0298	7.0345	0.0047
31	1e+12	NDD unbiased	7.0387	7.0253	-0.0134
32	1e+12	NDD unbiased	6.9932	6.9883	-0.0049
33	1e+12	NDD unbiased	7.0103	7.0057	-0.0046
44	5e+12	NDD unbiased	7.0488	7.0236	-0.0252
45	5e+12	NDD unbiased	7.0388	7.0091	-0.0297
46	5e+12	NDD unbiased	7.0918	7.0652	-0.0266
47	5e+12	NDD unbiased	7.037	7.009	-0.028
50	1e+13	NDD unbiased	6.9566	6.9149	-0.0417
51	1e+13	NDD unbiased	6.9583	6.9143	-0.044
52	1e+13	NDD unbiased	6.9585	6.9155	-0.043
53	1e+13	NDD unbiased	7.0075	6.9615	-0.046

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	6.9944	6.998	7.0016	0.0050912	7.0747	7.087	7.0994	0.017466	0.0731	0.08905	0.105	0.022557
1e+12	6.9932	7.018	7.0387	0.020347	6.9883	7.0134	7.0345	0.020624	-0.0134	-0.00455	0.0047	0.0073939
5e+12	7.037	7.0541	7.0918	0.025664	7.009	7.0267	7.0652	0.026551	-0.0297	-0.027375	-0.0252	0.0019259
1e+13	6.9566	6.9702	7.0075	0.024865	6.9143	6.9265	6.9615	0.023305	-0.046	-0.043675	-0.0417	0.0018136

Device Test: 61.4 V_BP5L(_V_BP5L PWM 1MHz VIN_12V)





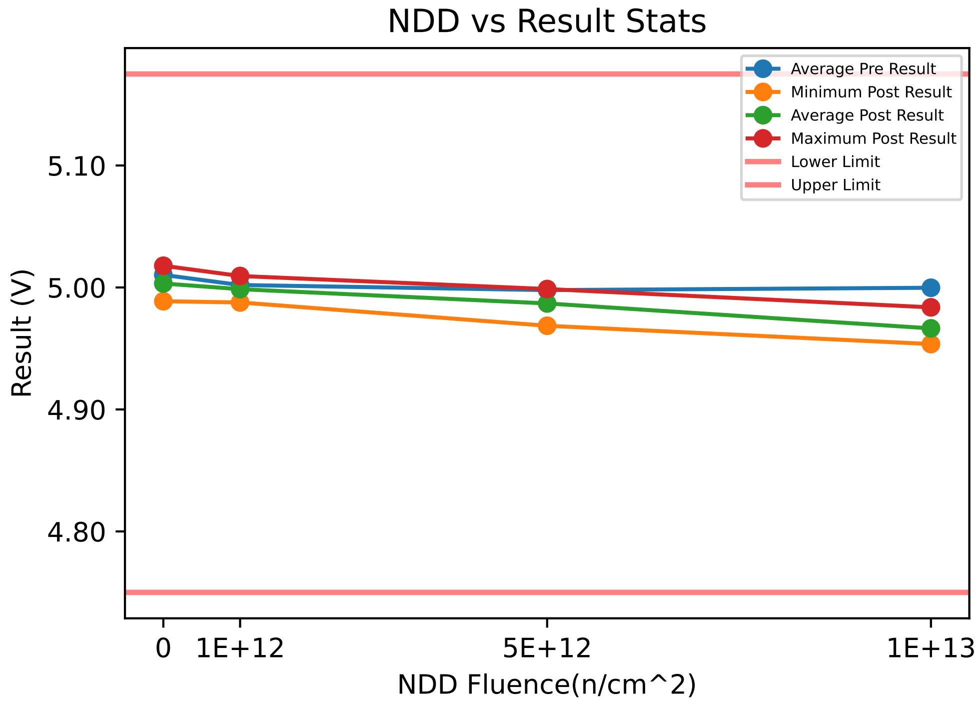
Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

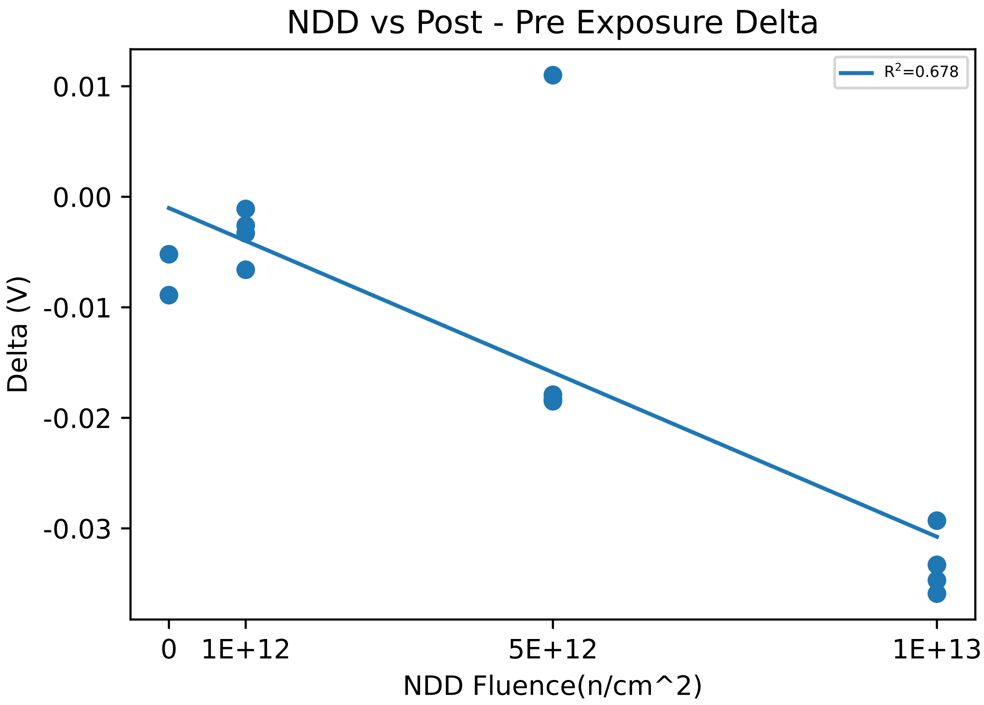
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	5.0173	4.9899	-0.0274
2	0	Correlation	5.0171	5.0197	0.0026
30	1e+12	NDD unbiased	5.0223	5.0005	-0.0218
31	1e+12	NDD unbiased	5.0028	5.0191	0.0163
32	1e+12	NDD unbiased	5.0026	4.9997	-0.0029
33	1e+12	NDD unbiased	4.991	4.9879	-0.0031
44	5e+12	NDD unbiased	4.9928	4.9766	-0.0162
45	5e+12	NDD unbiased	5.0169	4.9842	-0.0327
46	5e+12	NDD unbiased	5.0014	4.9836	-0.0178
47	5e+12	NDD unbiased	5.0035	4.9841	-0.0194
50	1e+13	NDD unbiased	4.9877	4.9555	-0.0322
51	1e+13	NDD unbiased	4.9997	4.9672	-0.0325
52	1e+13	NDD unbiased	5.016	4.9848	-0.0312
53	1e+13	NDD unbiased	4.9947	4.9615	-0.0332

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.0171	5.0172	5.0173	0.00014142	4.9899	5.0048	5.0197	0.021072	-0.0274	-0.0124	0.0026	0.021213
1e+12	4.991	5.0047	5.0223	0.01298	4.9879	5.0018	5.0191	0.012892	-0.0218	-0.002875	0.0163	0.015555
5e+12	4.9928	5.0037	5.0169	0.0099728	4.9766	4.9821	4.9842	0.0036927	-0.0327	-0.021525	-0.0162	0.0075637
1e+13	4.9877	4.9995	5.016	0.012036	4.9555	4.9672	4.9848	0.012638	-0.0332	-0.032275	-0.0312	0.00083016

Device Test: 61.5 V_BP5H(_V_BP5H PWM 1MHz VIN_12V)





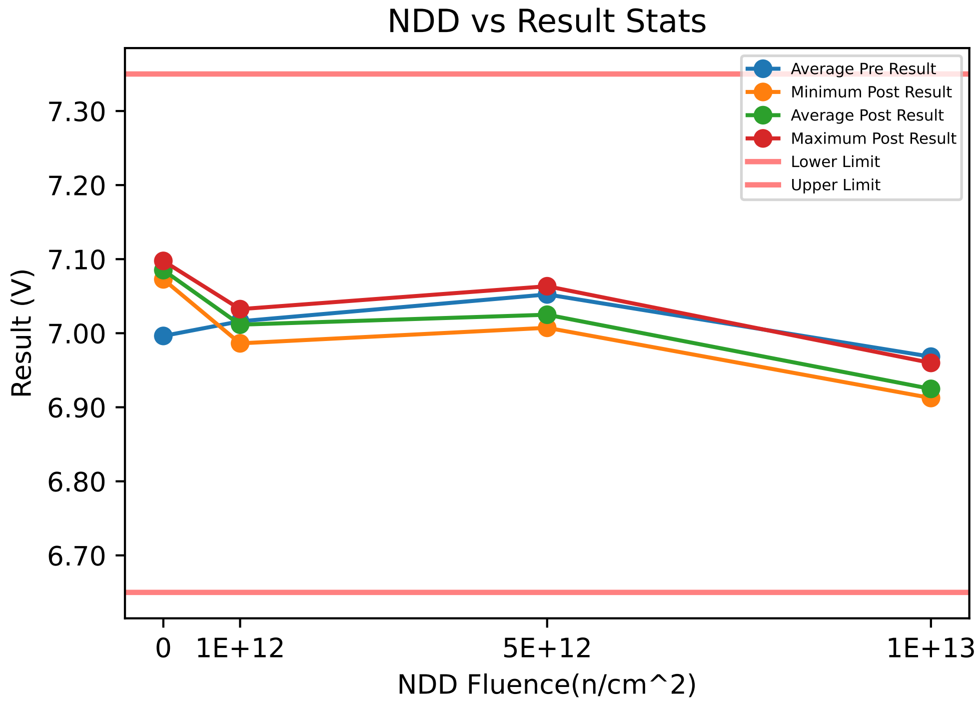
Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

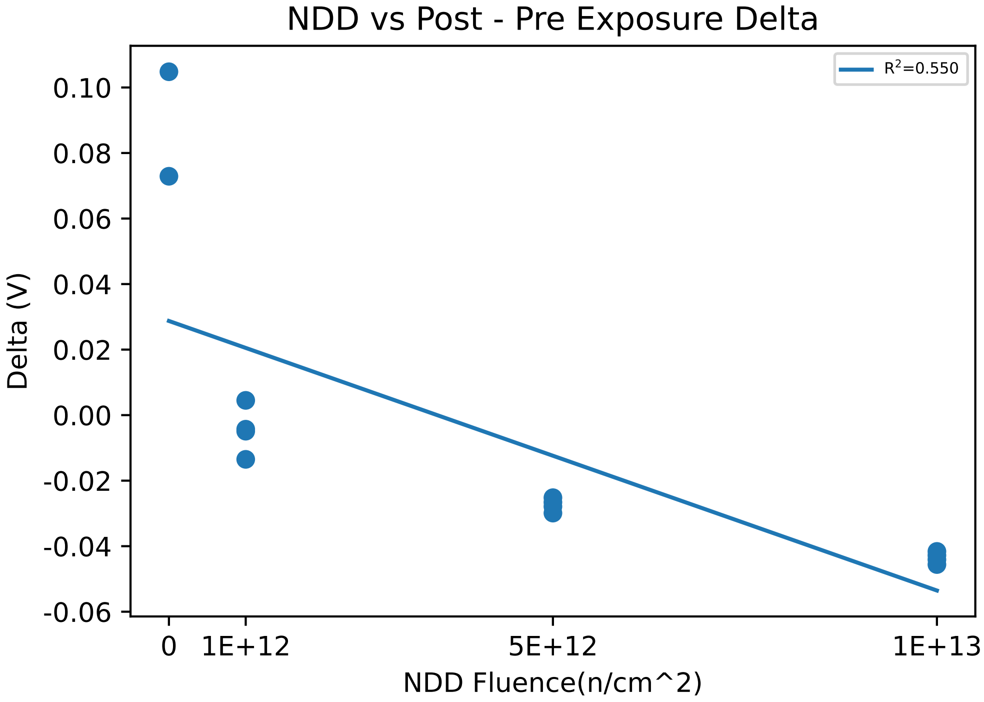
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	4.9976	4.9887	-0.0089
2	0	Correlation	5.023	5.0178	-0.0052
30	1e+12	NDD unbiased	4.9909	4.9898	-0.0011
31	1e+12	NDD unbiased	4.9943	4.9877	-0.0066
32	1e+12	NDD unbiased	5.0127	5.0094	-0.0033
33	1e+12	NDD unbiased	5.0101	5.0075	-0.0026
44	5e+12	NDD unbiased	4.9998	4.9819	-0.0179
45	5e+12	NDD unbiased	4.9877	4.9987	0.011
46	5e+12	NDD unbiased	4.9871	4.9686	-0.0185
47	5e+12	NDD unbiased	5.0167	4.9984	-0.0183
50	1e+13	NDD unbiased	5.017	4.9837	-0.0333
51	1e+13	NDD unbiased	4.9895	4.9536	-0.0359
52	1e+13	NDD unbiased	5.001	4.9717	-0.0293
53	1e+13	NDD unbiased	4.9915	4.9568	-0.0347

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.9976	5.0103	5.023	0.017961	4.9887	5.0032	5.0178	0.020577	-0.0089	-0.00705	-0.0052	0.0026163
1e+12	4.9909	5.002	5.0127	0.010994	4.9877	4.9986	5.0094	0.011432	-0.0066	-0.0034	-0.0011	0.0023224
5e+12	4.9871	4.9978	5.0167	0.013877	4.9686	4.9869	4.9987	0.014507	-0.0185	-0.010925	0.011	0.014619
1e+13	4.9895	4.9998	5.017	0.012547	4.9536	4.9665	4.9837	0.013945	-0.0359	-0.0333	-0.0293	0.0028705

Device Test: 61.6 V_BP7L(_V_BP7L PWM 2MHz VIN_12V)


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

Test Results (Lower Limit = 6.65, Upper Limit = 7.35 (V))

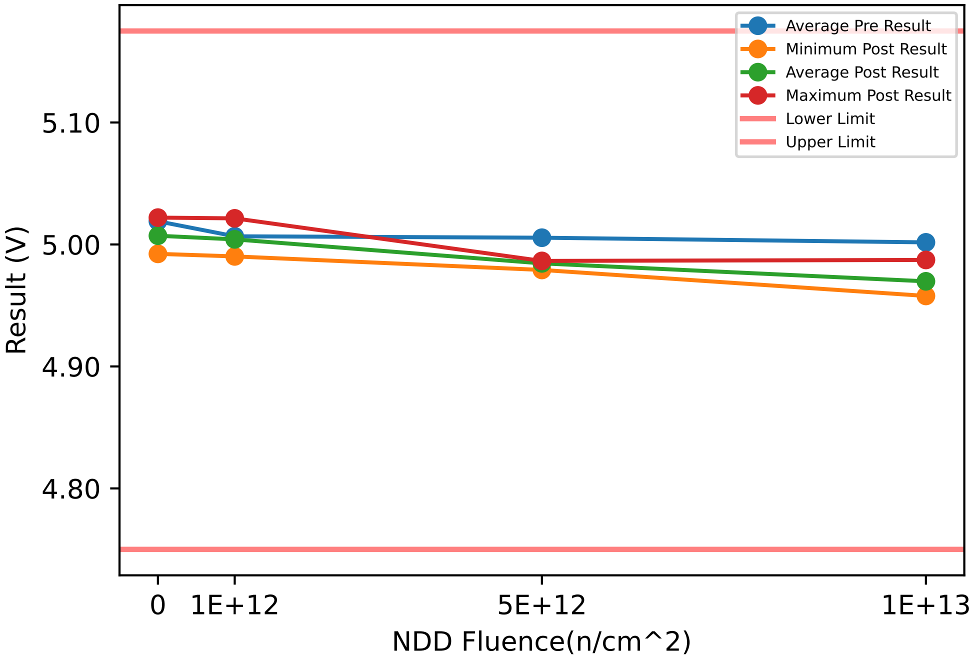
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	6.9998	7.0727	0.0729
2	0	Correlation	6.9928	7.0976	0.1048
30	1e+12	NDD unbiased	7.028	7.0325	0.0045
31	1e+12	NDD unbiased	7.037	7.0235	-0.0135
32	1e+12	NDD unbiased	6.9912	6.9863	-0.0049
33	1e+12	NDD unbiased	7.0081	7.0038	-0.0043
44	5e+12	NDD unbiased	7.047	7.0218	-0.0252
45	5e+12	NDD unbiased	7.0372	7.0073	-0.0299
46	5e+12	NDD unbiased	7.09	7.0634	-0.0266
47	5e+12	NDD unbiased	7.0352	7.0073	-0.0279
50	1e+13	NDD unbiased	6.9547	6.9131	-0.0416
51	1e+13	NDD unbiased	6.9566	6.9125	-0.0441
52	1e+13	NDD unbiased	6.9565	6.9137	-0.0428
53	1e+13	NDD unbiased	7.0055	6.9599	-0.0456

Test Statistics (V)

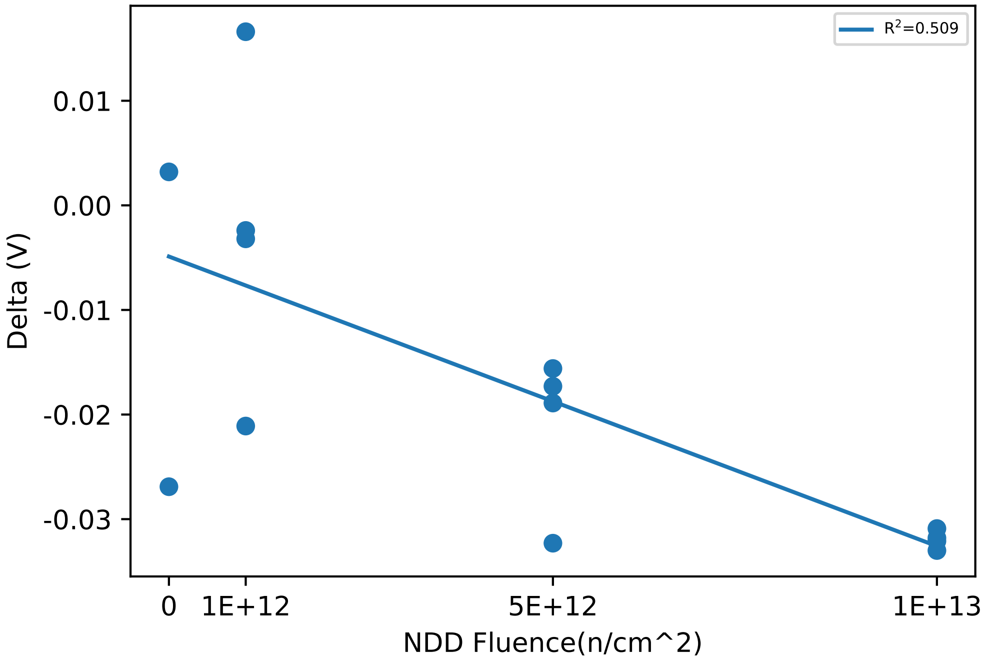
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	6.9928	6.9963	6.9998	0.0049497	7.0727	7.0852	7.0976	0.017607	0.0729	0.08885	0.1048	0.022557
1e+12	6.9912	7.0161	7.037	0.020514	6.9863	7.0115	7.0325	0.02065	-0.0135	-0.00455	0.0045	0.0073528
5e+12	7.0352	7.0523	7.09	0.025624	7.0073	7.0249	7.0634	0.026529	-0.0299	-0.0274	-0.0252	0.0019983
1e+13	6.9547	6.9683	7.0055	0.024799	6.9125	6.9248	6.9599	0.023405	-0.0456	-0.043525	-0.0416	0.0017193

Device Test: 61.7 V_BP5L(_V_BP5L PWM 2MHz VIN_12V)

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



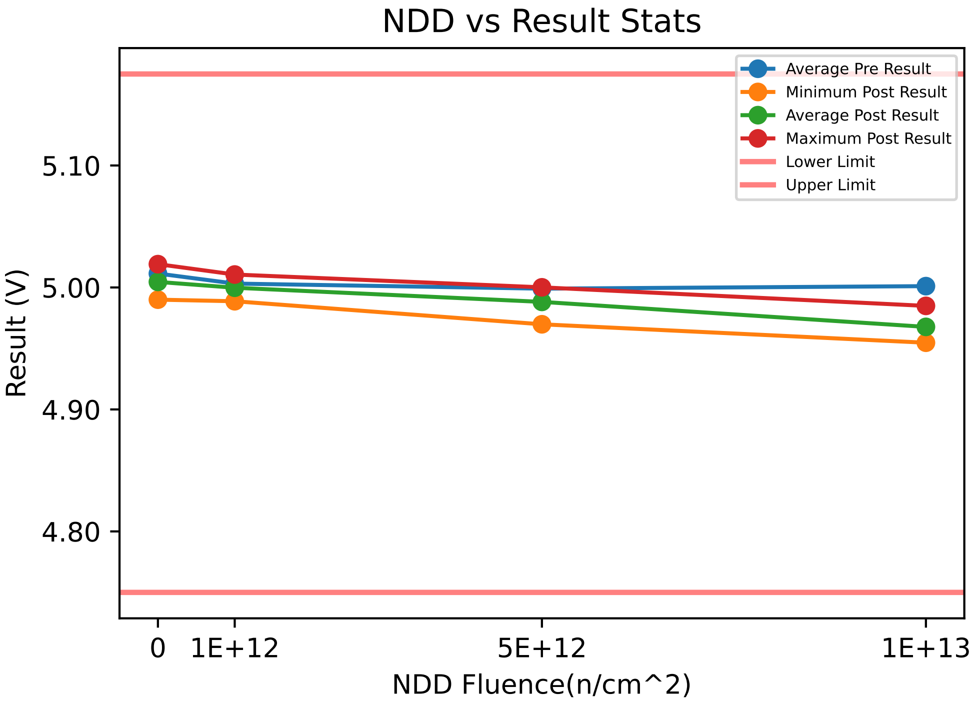
Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

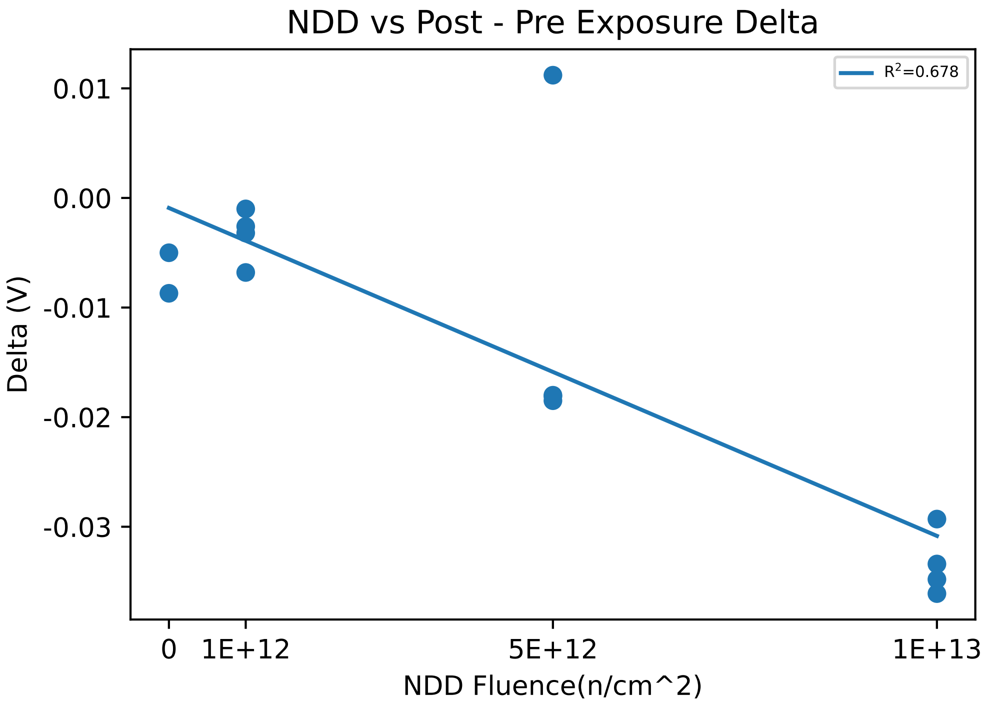
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	5.0192	4.9923	-0.0269
2	0	Correlation	5.0188	5.022	0.0032
30	1e+12	NDD unbiased	5.0241	5.003	-0.0211
31	1e+12	NDD unbiased	5.0048	5.0214	0.0166
32	1e+12	NDD unbiased	5.0045	5.0021	-0.0024
33	1e+12	NDD unbiased	4.9934	4.9902	-0.0032
44	5e+12	NDD unbiased	4.9947	4.9791	-0.0156
45	5e+12	NDD unbiased	5.0188	4.9865	-0.0323
46	5e+12	NDD unbiased	5.0033	4.986	-0.0173
47	5e+12	NDD unbiased	5.0053	4.9864	-0.0189
50	1e+13	NDD unbiased	4.9899	4.9578	-0.0321
51	1e+13	NDD unbiased	5.0018	4.97	-0.0318
52	1e+13	NDD unbiased	5.0182	4.9873	-0.0309
53	1e+13	NDD unbiased	4.997	4.964	-0.033

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.0188	5.019	5.0192	0.00028284	4.9923	5.0072	5.022	0.021001	-0.0269	-0.01185	0.0032	0.021284
1e+12	4.9934	5.0067	5.0241	0.012755	4.9902	5.0042	5.0214	0.01288	-0.0211	-0.002525	0.0166	0.015398
5e+12	4.9947	5.0055	5.0188	0.0099734	4.9791	4.9845	4.9865	0.0036065	-0.0323	-0.021025	-0.0156	0.0076365
1e+13	4.9899	5.0017	5.0182	0.012022	4.9578	4.9698	4.9873	0.012701	-0.033	-0.03195	-0.0309	0.00086603

Device Test: 61.8 V_BP5H(_V_BP5H PWM 2MHz VIN_12V)





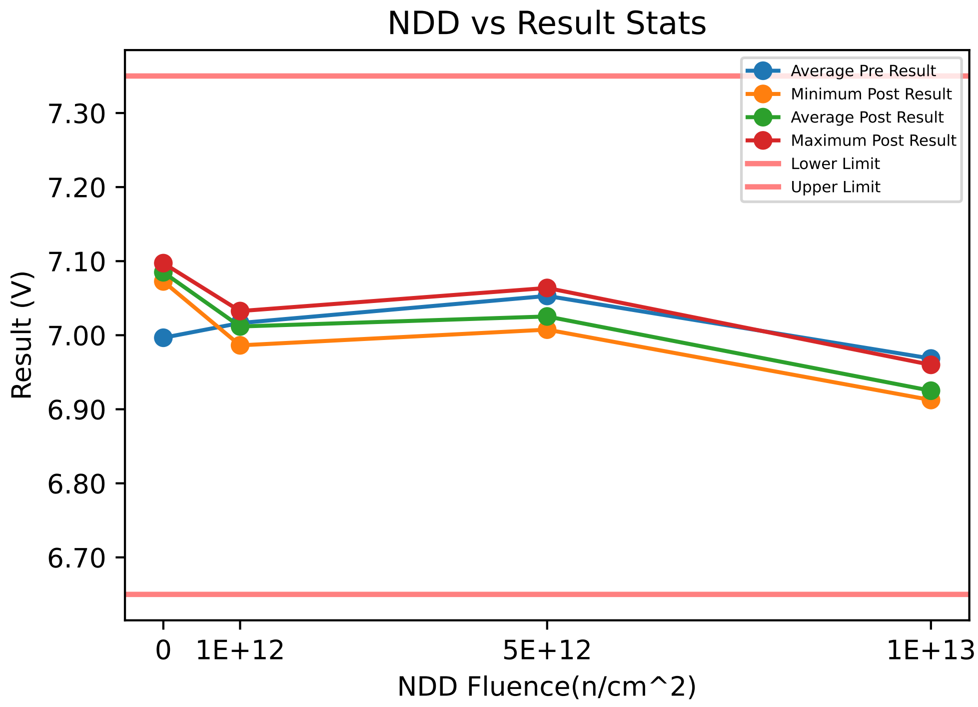
Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

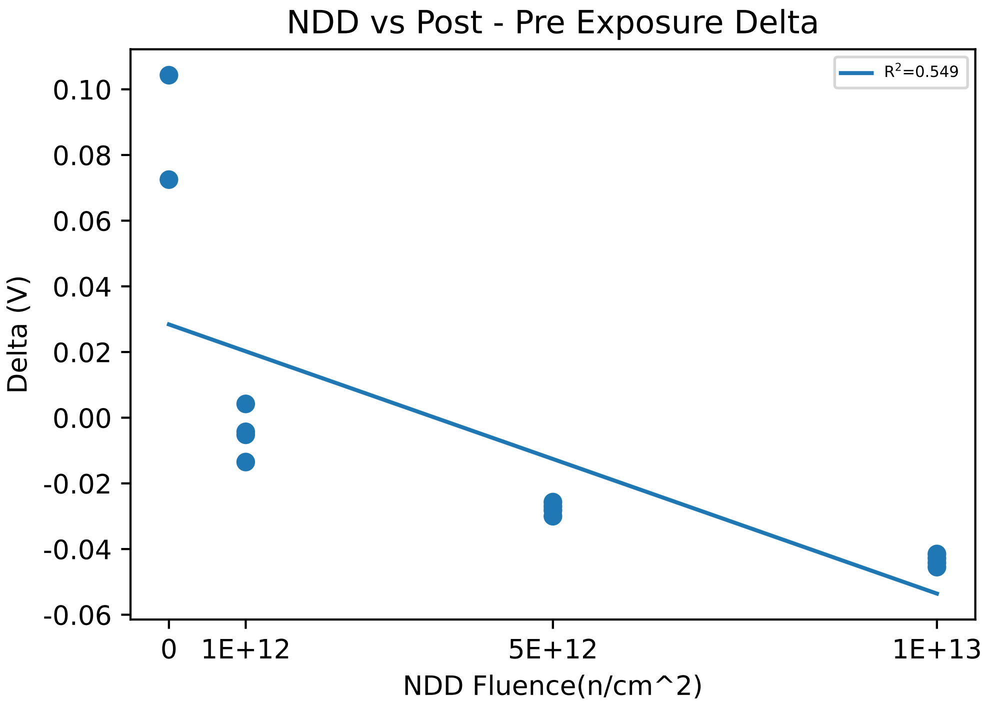
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	4.9987	4.99	-0.0087
2	0	Correlation	5.0241	5.0191	-0.005
30	1e+12	NDD unbiased	4.9921	4.9911	-0.001
31	1e+12	NDD unbiased	4.9955	4.9887	-0.0068
32	1e+12	NDD unbiased	5.0138	5.0106	-0.0032
33	1e+12	NDD unbiased	5.0113	5.0087	-0.0026
44	5e+12	NDD unbiased	5.0011	4.9831	-0.018
45	5e+12	NDD unbiased	4.9889	5.0001	0.0112
46	5e+12	NDD unbiased	4.9883	4.9698	-0.0185
47	5e+12	NDD unbiased	5.0178	4.9997	-0.0181
50	1e+13	NDD unbiased	5.0183	4.9849	-0.0334
51	1e+13	NDD unbiased	4.9908	4.9547	-0.0361
52	1e+13	NDD unbiased	5.0022	4.9729	-0.0293
53	1e+13	NDD unbiased	4.993	4.9582	-0.0348

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.9987	5.0114	5.0241	0.017961	4.99	5.0046	5.0191	0.020577	-0.0087	-0.00685	-0.005	0.0026163
1e+12	4.9921	5.0032	5.0138	0.010962	4.9887	4.9998	5.0106	0.011471	-0.0068	-0.0034	-0.001	0.0024495
5e+12	4.9883	4.999	5.0178	0.013837	4.9698	4.9882	5.0001	0.014588	-0.0185	-0.01085	0.0112	0.014702
1e+13	4.9908	5.0011	5.0183	0.0125	4.9547	4.9677	4.9849	0.01393	-0.0361	-0.0334	-0.0293	0.0029473

Device Test: 61.9 V_BP7L(_V_BP7L PWM 5MHz VIN_12V)





Test Results (Lower Limit = 6.65, Upper Limit = 7.35 (V))

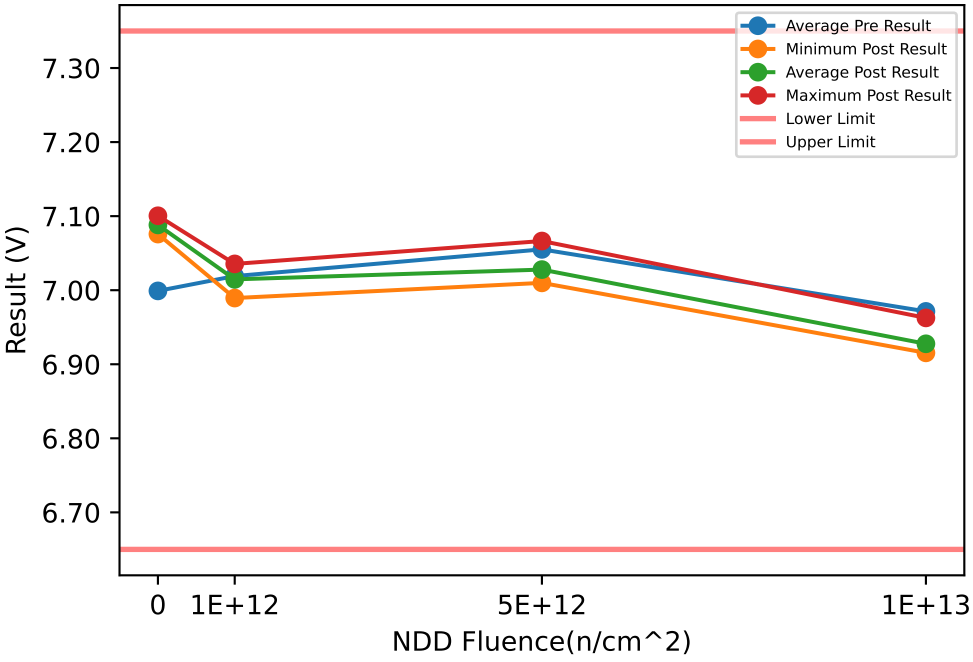
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	7.0001	7.0726	0.0725
2	0	Correlation	6.993	7.0973	0.1043
30	1e+12	NDD unbiased	7.0284	7.0326	0.0042
31	1e+12	NDD unbiased	7.0372	7.0237	-0.0135
32	1e+12	NDD unbiased	6.9915	6.9863	-0.0052
33	1e+12	NDD unbiased	7.0087	7.0044	-0.0043
44	5e+12	NDD unbiased	7.0479	7.0222	-0.0257
45	5e+12	NDD unbiased	7.0377	7.0077	-0.03
46	5e+12	NDD unbiased	7.0908	7.0638	-0.027
47	5e+12	NDD unbiased	7.0357	7.0075	-0.0282
50	1e+13	NDD unbiased	6.9549	6.9134	-0.0415
51	1e+13	NDD unbiased	6.9567	6.9125	-0.0442
52	1e+13	NDD unbiased	6.957	6.9142	-0.0428
53	1e+13	NDD unbiased	7.0055	6.96	-0.0455

Test Statistics (V)

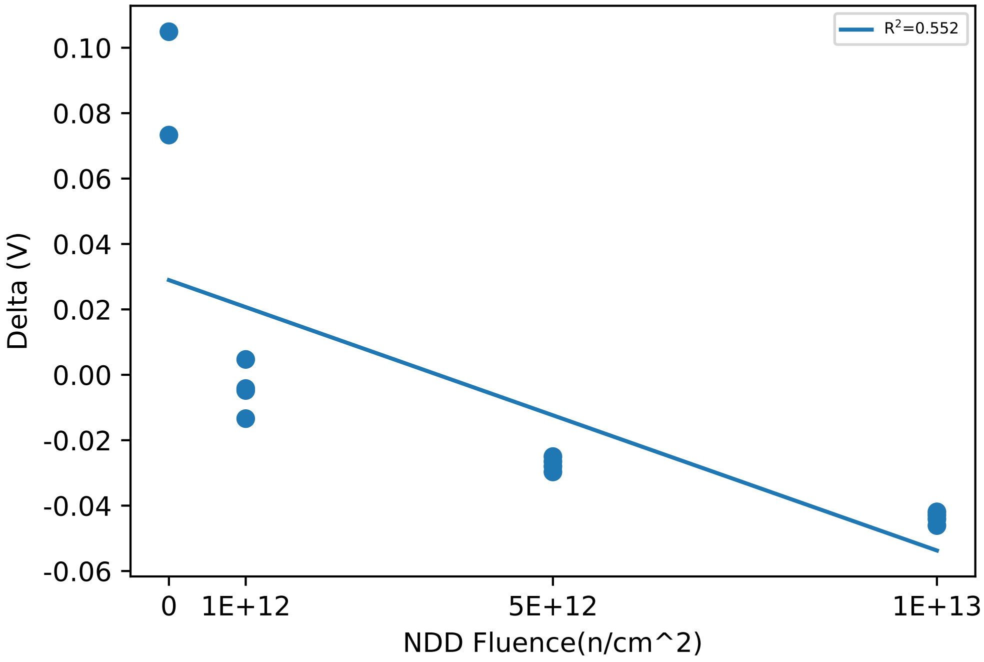
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	6.993	6.9966	7.0001	0.0050205	7.0726	7.085	7.0973	0.017466	0.0725	0.0884	0.1043	0.022486
1e+12	6.9915	7.0165	7.0372	0.020461	6.9863	7.0118	7.0326	0.02065	-0.0135	-0.0047	0.0042	0.0072356
5e+12	7.0357	7.053	7.0908	0.025744	7.0075	7.0253	7.0638	0.026574	-0.03	-0.027725	-0.0257	0.0018283
1e+13	6.9549	6.9685	7.0055	0.024667	6.9125	6.925	6.96	0.023327	-0.0455	-0.0435	-0.0415	0.0017301

Device Test: 62.0 V_BP7L(_V_BP7L PWM 500kHz VIN_14V)

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



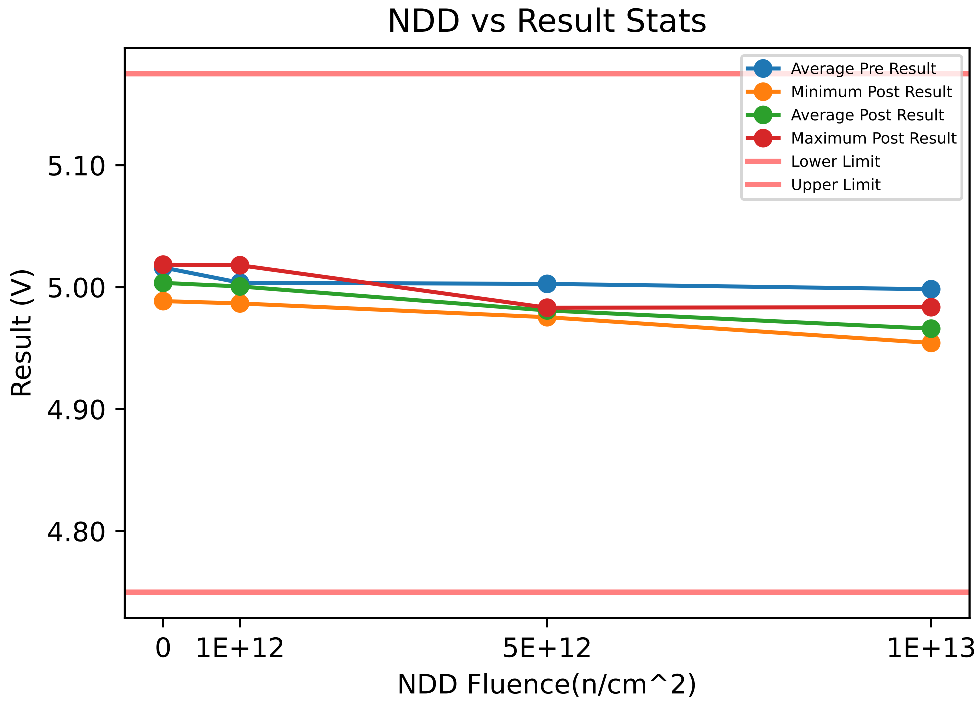
Test Results (Lower Limit = 6.65, Upper Limit = 7.35 (V))

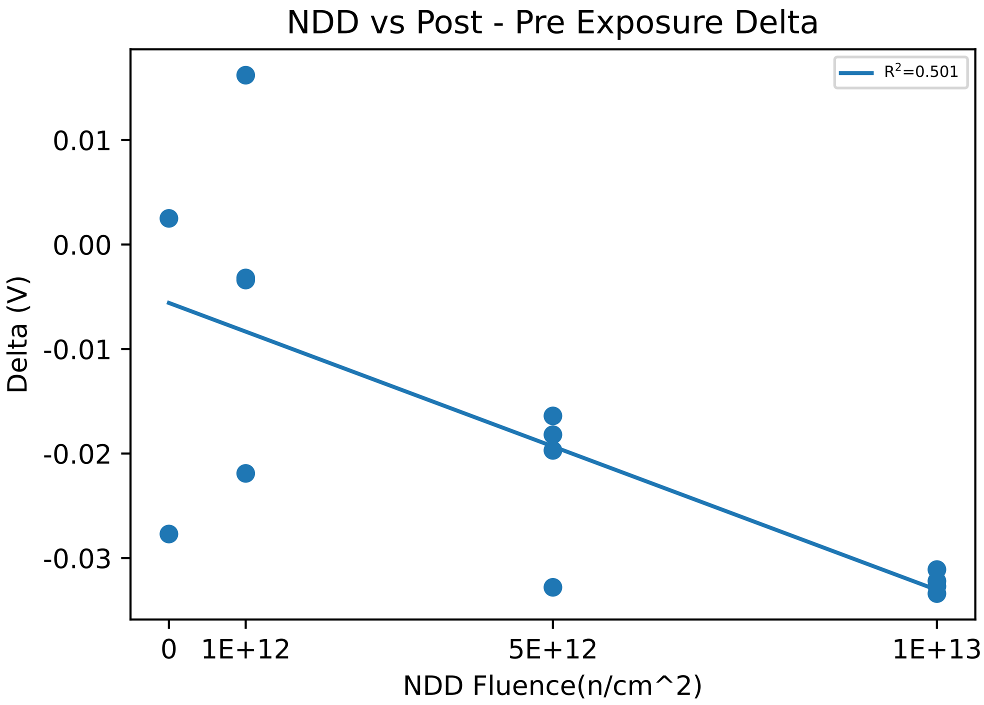
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	7.0025	7.0758	0.0733
2	0	Correlation	6.9956	7.1005	0.1049
30	1e+12	NDD unbiased	7.0308	7.0355	0.0047
31	1e+12	NDD unbiased	7.0398	7.0264	-0.0134
32	1e+12	NDD unbiased	6.9942	6.9894	-0.0048
33	1e+12	NDD unbiased	7.0114	7.0072	-0.0042
44	5e+12	NDD unbiased	7.0497	7.0247	-0.025
45	5e+12	NDD unbiased	7.04	7.0103	-0.0297
46	5e+12	NDD unbiased	7.0929	7.0664	-0.0265
47	5e+12	NDD unbiased	7.0379	7.0099	-0.028
50	1e+13	NDD unbiased	6.9578	6.9159	-0.0419
51	1e+13	NDD unbiased	6.9595	6.9154	-0.0441
52	1e+13	NDD unbiased	6.9595	6.9166	-0.0429
53	1e+13	NDD unbiased	7.0087	6.9626	-0.0461

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	6.9956	6.9991	7.0025	0.004879	7.0758	7.0882	7.1005	0.017466	0.0733	0.0891	0.1049	0.022345
1e+12	6.9942	7.0191	7.0398	0.020369	6.9894	7.0146	7.0355	0.020541	-0.0134	-0.004425	0.0047	0.0073939
5e+12	7.0379	7.0551	7.0929	0.025702	7.0099	7.0278	7.0664	0.026622	-0.0297	-0.0273	-0.025	0.0020149
1e+13	6.9578	6.9714	7.0087	0.024896	6.9154	6.9276	6.9626	0.023322	-0.0461	-0.04375	-0.0419	0.0018065

Device Test: 62.1 V_BP5L(_V_BP5L PWM 500kHz VIN_14V)





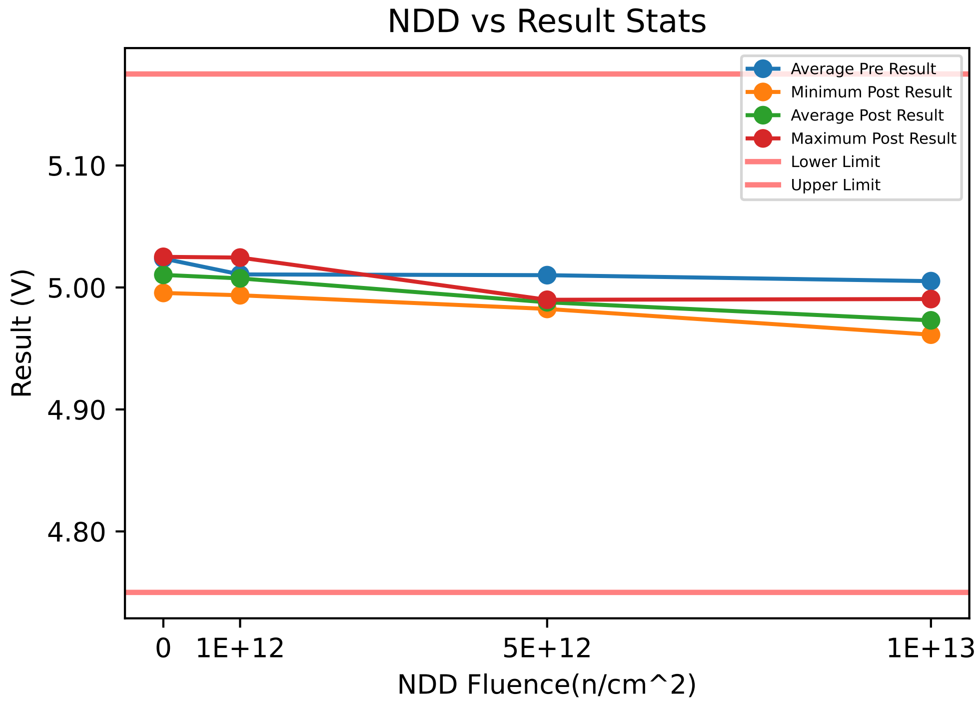
Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

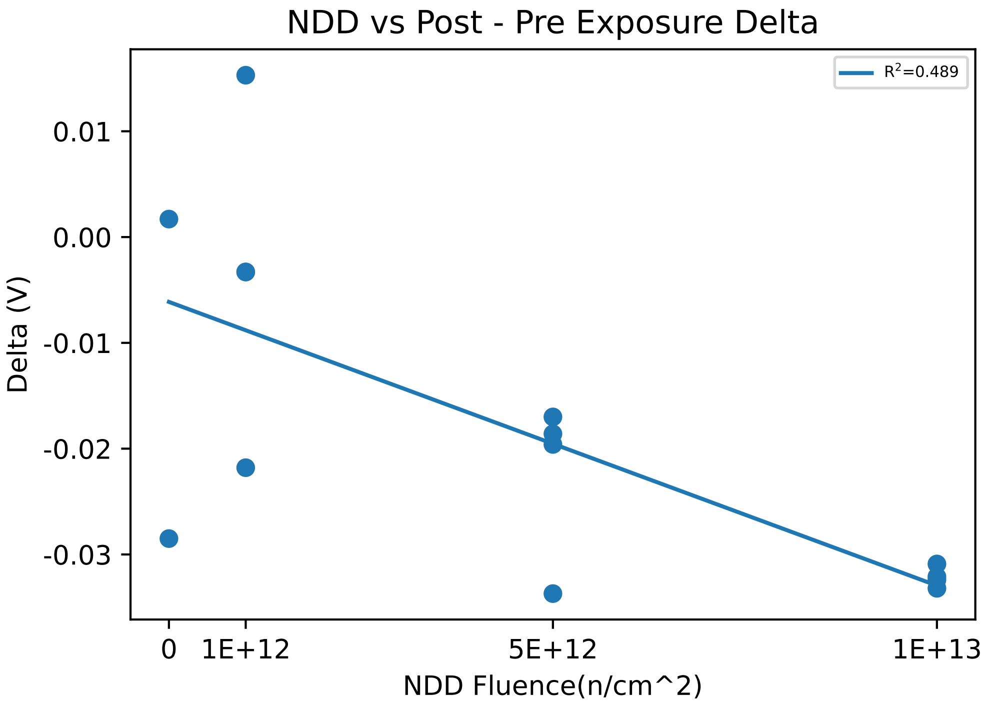
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	5.0163	4.9886	-0.0277
2	0	Correlation	5.016	5.0185	0.0025
30	1e+12	NDD unbiased	5.0213	4.9994	-0.0219
31	1e+12	NDD unbiased	5.0018	5.018	0.0162
32	1e+12	NDD unbiased	5.0018	4.9984	-0.0034
33	1e+12	NDD unbiased	4.9899	4.9867	-0.0032
44	5e+12	NDD unbiased	4.9918	4.9754	-0.0164
45	5e+12	NDD unbiased	5.016	4.9832	-0.0328
46	5e+12	NDD unbiased	5.0005	4.9823	-0.0182
47	5e+12	NDD unbiased	5.0026	4.9829	-0.0197
50	1e+13	NDD unbiased	4.9865	4.9543	-0.0322
51	1e+13	NDD unbiased	4.9986	4.9659	-0.0327
52	1e+13	NDD unbiased	5.0147	4.9836	-0.0311
53	1e+13	NDD unbiased	4.9936	4.9602	-0.0334

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.016	5.0161	5.0163	0.00021213	4.9886	5.0036	5.0185	0.021142	-0.0277	-0.0126	0.0025	0.021355
1e+12	4.9899	5.0037	5.0213	0.013005	4.9867	5.0006	5.018	0.012939	-0.0219	-0.003075	0.0162	0.015557
5e+12	4.9918	5.0027	5.016	0.010009	4.9754	4.9809	4.9832	0.0037189	-0.0328	-0.021775	-0.0164	0.0074728
1e+13	4.9865	4.9984	5.0147	0.011977	4.9543	4.966	4.9836	0.012653	-0.0334	-0.03235	-0.0311	0.00096782

Device Test: 62.10 V_BP5L(_V_BP5L PWM 5MHz VIN_14V)


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

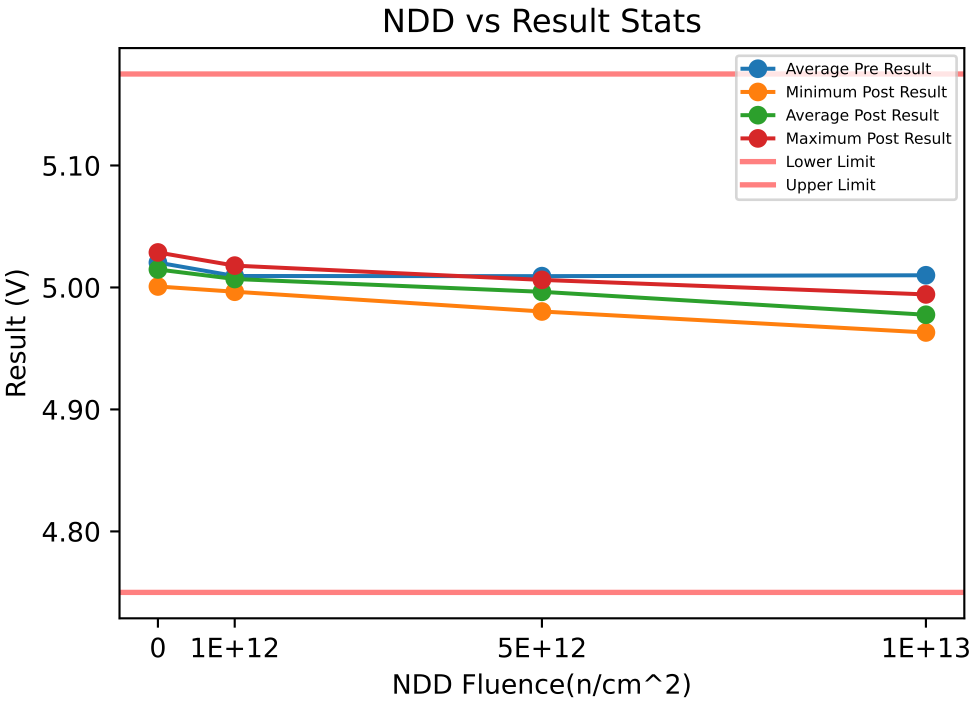
Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

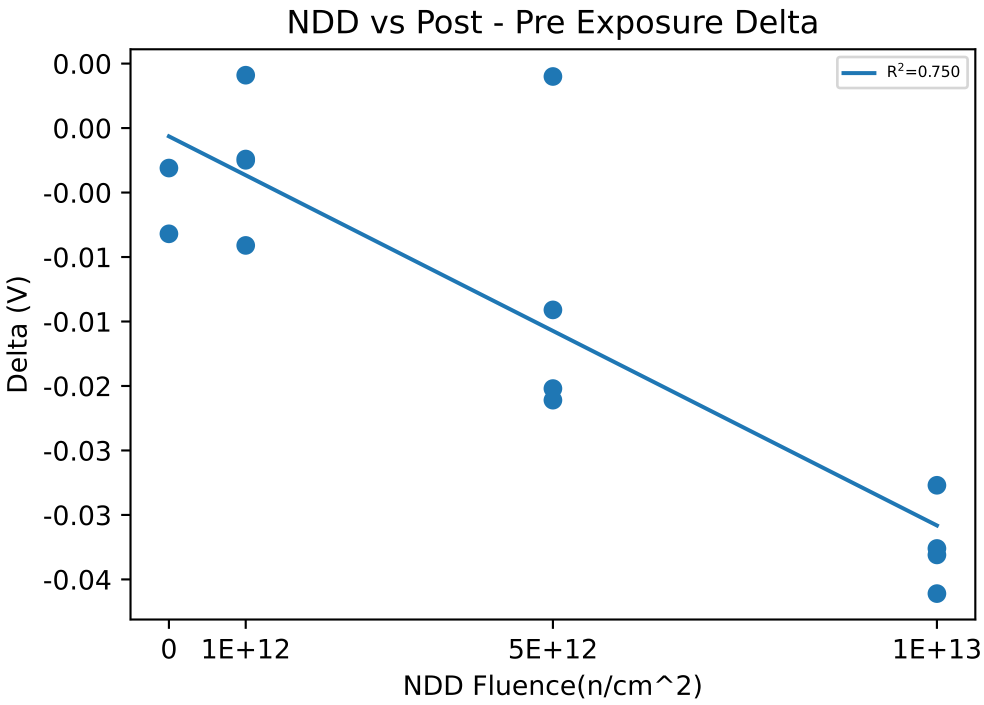
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	5.024	4.9955	-0.0285
2	0	Correlation	5.0234	5.0251	0.0017
30	1e+12	NDD unbiased	5.0279	5.0061	-0.0218
31	1e+12	NDD unbiased	5.0092	5.0245	0.0153
32	1e+12	NDD unbiased	5.0088	5.0055	-0.0033
33	1e+12	NDD unbiased	4.9969	4.9936	-0.0033
44	5e+12	NDD unbiased	4.9994	4.9824	-0.017
45	5e+12	NDD unbiased	5.0236	4.9899	-0.0337
46	5e+12	NDD unbiased	5.0079	4.9893	-0.0186
47	5e+12	NDD unbiased	5.0094	4.9898	-0.0196
50	1e+13	NDD unbiased	4.9934	4.9613	-0.0321
51	1e+13	NDD unbiased	5.0055	4.9731	-0.0324
52	1e+13	NDD unbiased	5.0214	4.9905	-0.0309
53	1e+13	NDD unbiased	5.0004	4.9672	-0.0332

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.0234	5.0237	5.024	0.00042426	4.9955	5.0103	5.0251	0.02093	-0.0285	-0.0134	0.0017	0.021355
1e+12	4.9969	5.0107	5.0279	0.012808	4.9936	5.0074	5.0245	0.012756	-0.0218	-0.003275	0.0153	0.015146
5e+12	4.9994	5.0101	5.0236	0.010034	4.9824	4.9878	4.9899	0.0036428	-0.0337	-0.022225	-0.017	0.0077246
1e+13	4.9934	5.0052	5.0214	0.0119	4.9613	4.973	4.9905	0.012607	-0.0332	-0.03215	-0.0309	0.00095394

Device Test: 62.11 V_BP5H(_V_BP5H PWM 5MHz VIN_14V)





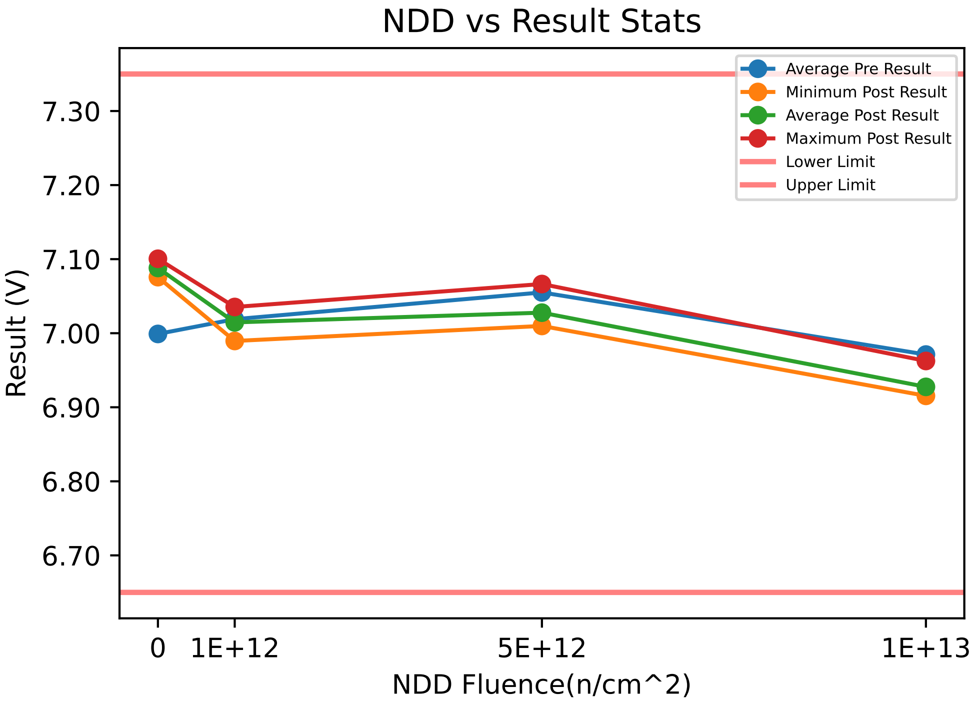
Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

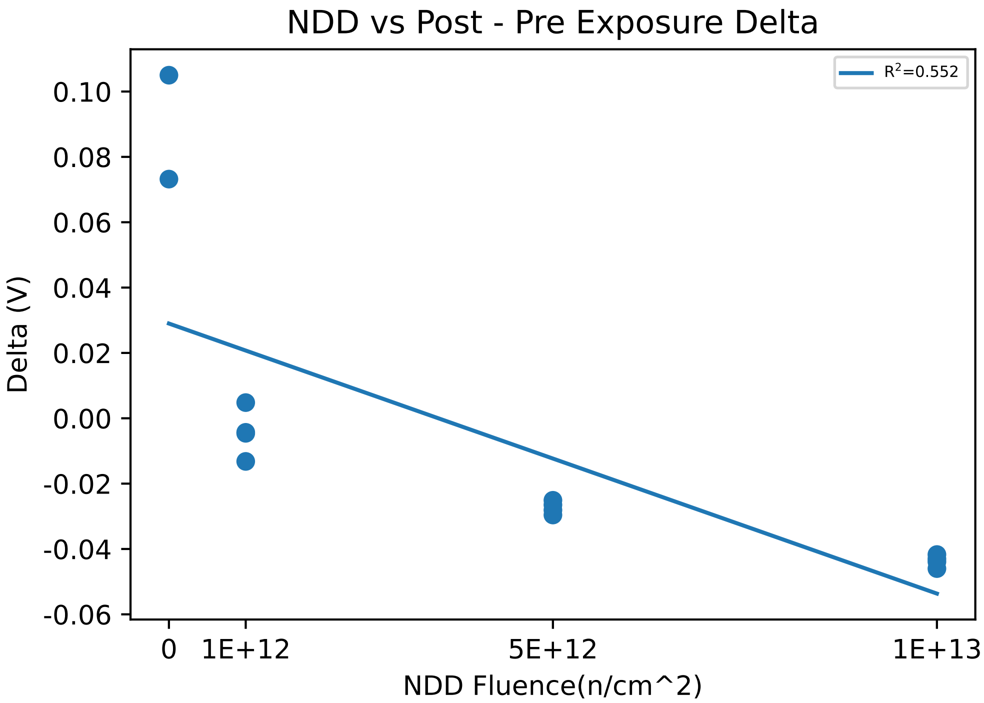
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	5.0039	5.0008	-0.0031
2	0	Correlation	5.0369	5.0287	-0.0082
30	1e+12	NDD unbiased	4.9966	5.0007	0.0041
31	1e+12	NDD unbiased	5.0056	4.9965	-0.0091
32	1e+12	NDD unbiased	5.015	5.0126	-0.0024
33	1e+12	NDD unbiased	5.0204	5.0179	-0.0025
44	5e+12	NDD unbiased	5.0143	4.9941	-0.0202
45	5e+12	NDD unbiased	5.0011	5.0051	0.004
46	5e+12	NDD unbiased	5.0014	4.9803	-0.0211
47	5e+12	NDD unbiased	5.0203	5.0062	-0.0141
50	1e+13	NDD unbiased	5.0269	4.9943	-0.0326
51	1e+13	NDD unbiased	4.9962	4.9631	-0.0331
52	1e+13	NDD unbiased	5.0111	4.9834	-0.0277
53	1e+13	NDD unbiased	5.0058	4.9697	-0.0361

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.0039	5.0204	5.0369	0.023335	5.0008	5.0147	5.0287	0.019728	-0.0082	-0.00565	-0.0031	0.0036062
1e+12	4.9966	5.0094	5.0204	0.010498	4.9965	5.0069	5.0179	0.010001	-0.0091	-0.002475	0.0041	0.0053891
5e+12	5.0011	5.0093	5.0203	0.0095855	4.9803	4.9964	5.0062	0.012059	-0.0211	-0.01285	0.004	0.011656
1e+13	4.9962	5.01	5.0269	0.012844	4.9631	4.9776	4.9943	0.013966	-0.0361	-0.032375	-0.0277	0.0034789

Device Test: 62.12 V_BP7L(_V_BP7L IIM 500kHz VIN_14V)


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

Test Results (Lower Limit = 6.65, Upper Limit = 7.35 (V))

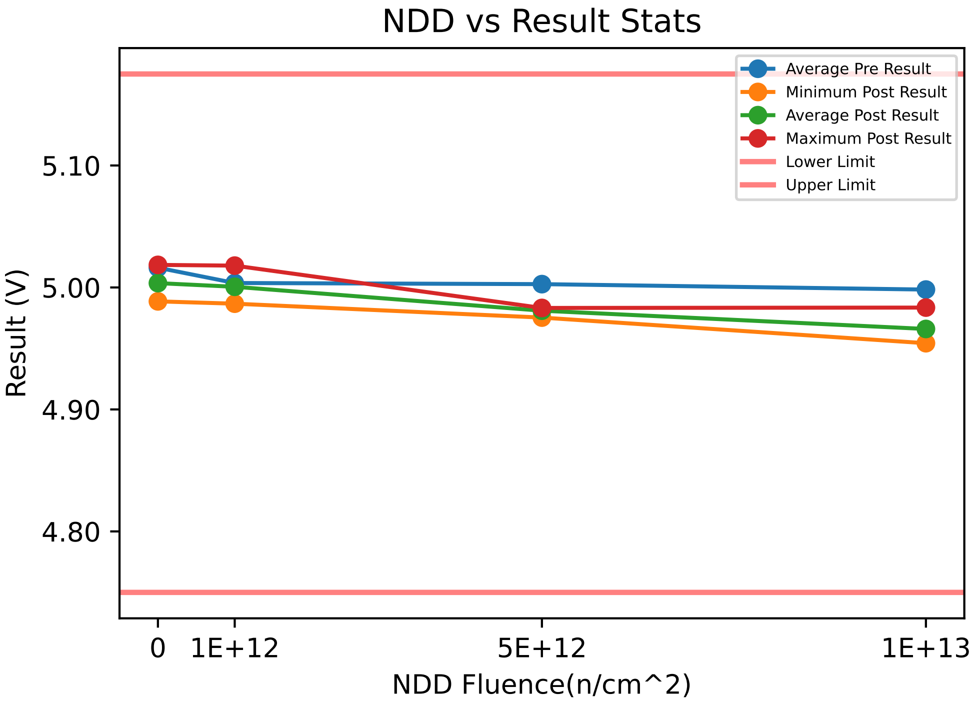
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	7.0025	7.0757	0.0732
2	0	Correlation	6.9955	7.1005	0.105
30	1e+12	NDD unbiased	7.0306	7.0354	0.0048
31	1e+12	NDD unbiased	7.0396	7.0264	-0.0132
32	1e+12	NDD unbiased	6.9941	6.9895	-0.0046
33	1e+12	NDD unbiased	7.0114	7.0071	-0.0043
44	5e+12	NDD unbiased	7.0497	7.0246	-0.0251
45	5e+12	NDD unbiased	7.0397	7.0101	-0.0296
46	5e+12	NDD unbiased	7.0929	7.0664	-0.0265
47	5e+12	NDD unbiased	7.0379	7.0098	-0.0281
50	1e+13	NDD unbiased	6.9575	6.9158	-0.0417
51	1e+13	NDD unbiased	6.9593	6.9154	-0.0439
52	1e+13	NDD unbiased	6.9594	6.9164	-0.043
53	1e+13	NDD unbiased	7.0085	6.9625	-0.046

Test Statistics (V)

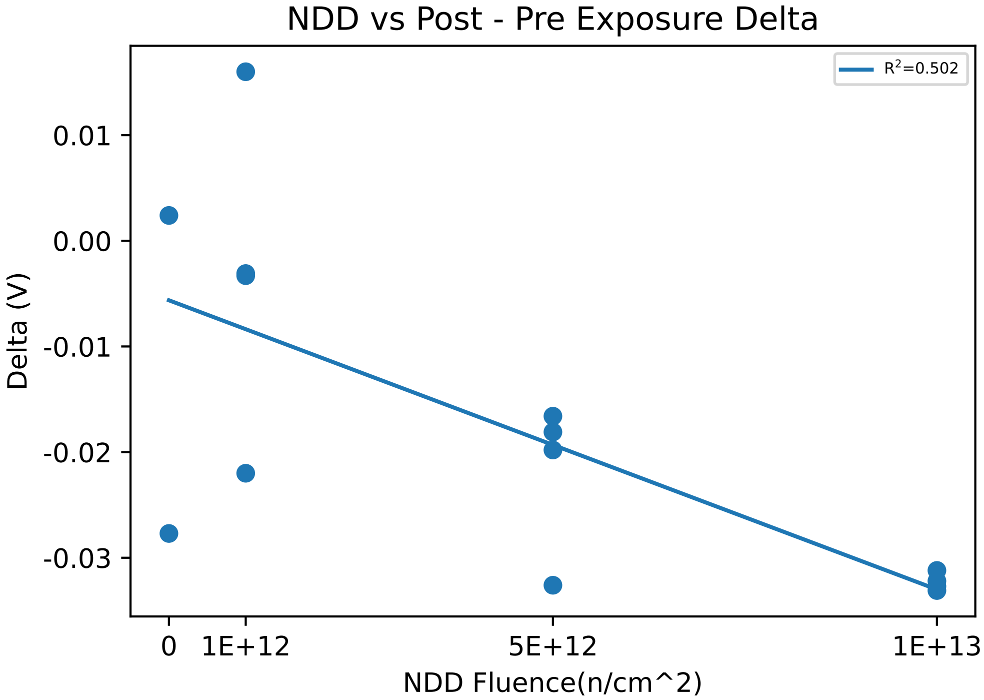
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	6.9955	6.999	7.0025	0.0049497	7.0757	7.0881	7.1005	0.017536	0.0732	0.0891	0.105	0.022486
1e+12	6.9941	7.0189	7.0396	0.020303	6.9895	7.0146	7.0354	0.020479	-0.0132	-0.004325	0.0048	0.0073509
5e+12	7.0379	7.055	7.0929	0.025762	7.0098	7.0277	7.0664	0.026692	-0.0296	-0.027325	-0.0251	0.00195
1e+13	6.9575	6.9712	7.0085	0.024899	6.9154	6.9275	6.9625	0.02332	-0.046	-0.04365	-0.0417	0.0018083

Device Test: 62.13 V_BP5L(_V_BP5L IIM 500kHz VIN_14V)

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



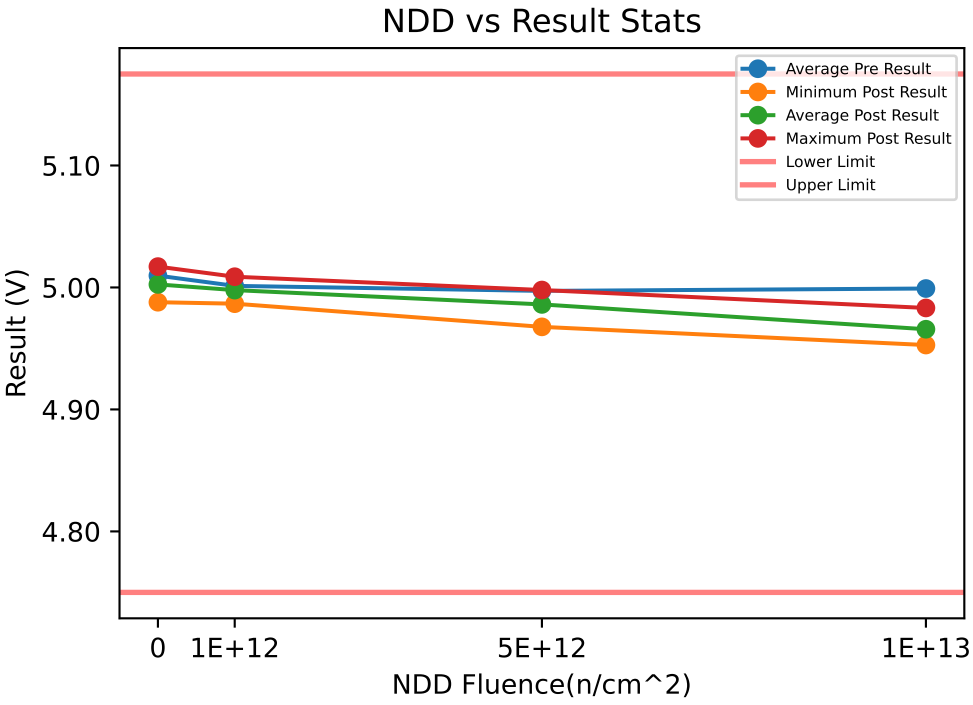
Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

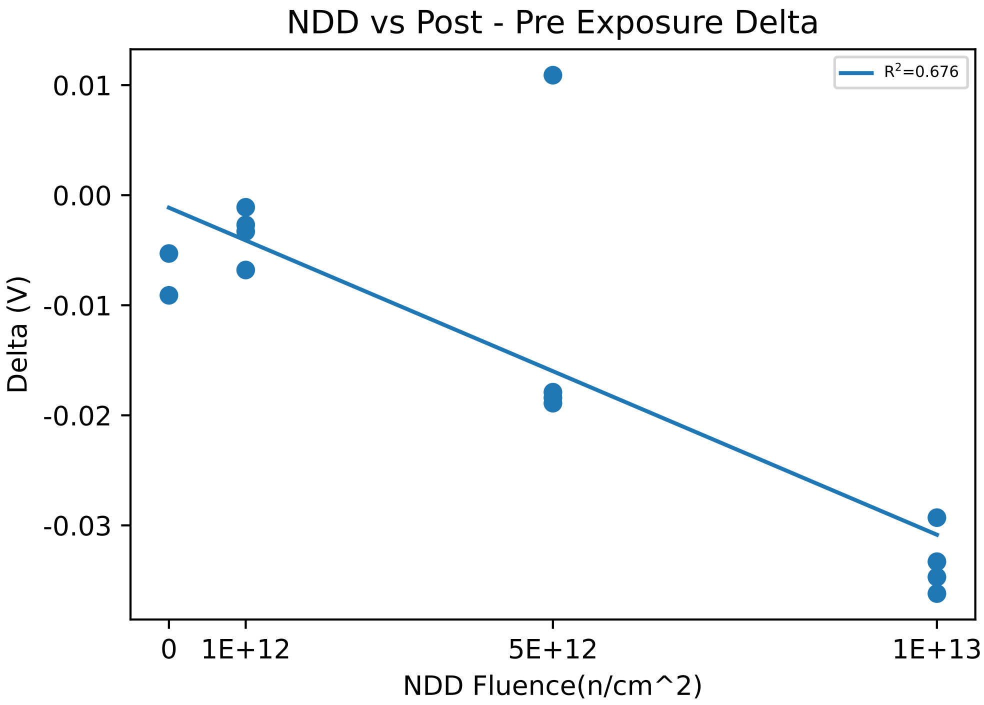
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	5.0163	4.9886	-0.0277
2	0	Correlation	5.0161	5.0185	0.0024
30	1e+12	NDD unbiased	5.0212	4.9992	-0.022
31	1e+12	NDD unbiased	5.0019	5.0179	0.016
32	1e+12	NDD unbiased	5.0017	4.9984	-0.0033
33	1e+12	NDD unbiased	4.9898	4.9867	-0.0031
44	5e+12	NDD unbiased	4.9919	4.9753	-0.0166
45	5e+12	NDD unbiased	5.0158	4.9832	-0.0326
46	5e+12	NDD unbiased	5.0004	4.9823	-0.0181
47	5e+12	NDD unbiased	5.0028	4.983	-0.0198
50	1e+13	NDD unbiased	4.9865	4.9543	-0.0322
51	1e+13	NDD unbiased	4.9985	4.9658	-0.0327
52	1e+13	NDD unbiased	5.0147	4.9835	-0.0312
53	1e+13	NDD unbiased	4.9934	4.9603	-0.0331

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.0161	5.0162	5.0163	0.00014142	4.9886	5.0036	5.0185	0.021142	-0.0277	-0.01265	0.0024	0.021284
1e+12	4.9898	5.0037	5.0212	0.012996	4.9867	5.0006	5.0179	0.012901	-0.022	-0.0031	0.016	0.015514
5e+12	4.9919	5.0027	5.0158	0.0098919	4.9753	4.9809	4.9832	0.0037864	-0.0326	-0.021775	-0.0166	0.0073341
1e+13	4.9865	4.9983	5.0147	0.012003	4.9543	4.966	4.9835	0.012592	-0.0331	-0.0323	-0.0312	0.00082057

Device Test: 62.14 V_BP5H(_V_BP5H IIM 500kHz VIN_14V)





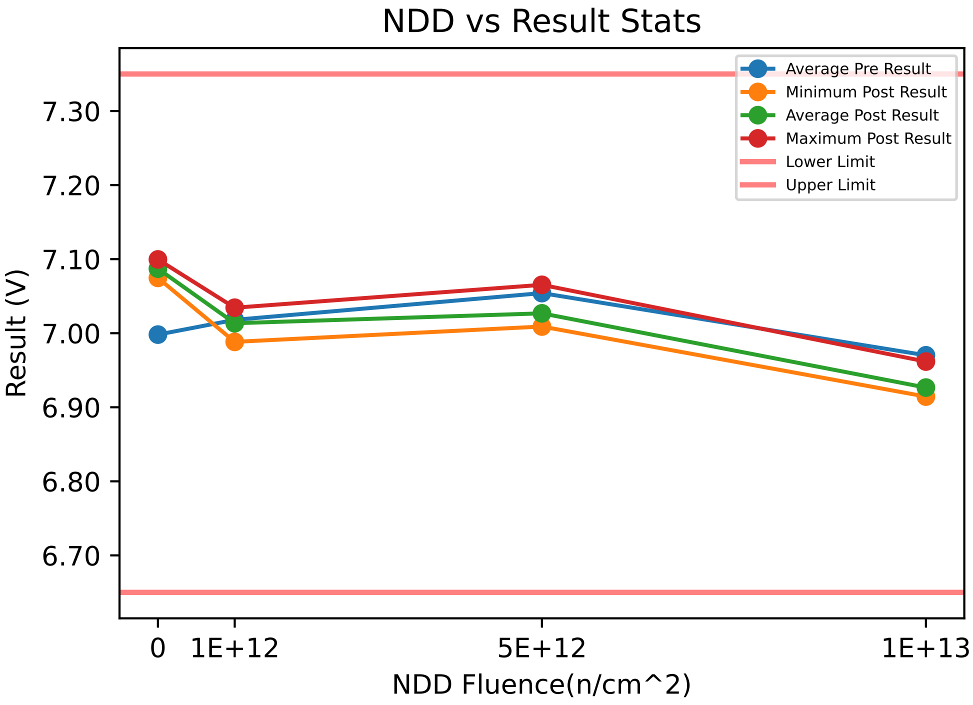
Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

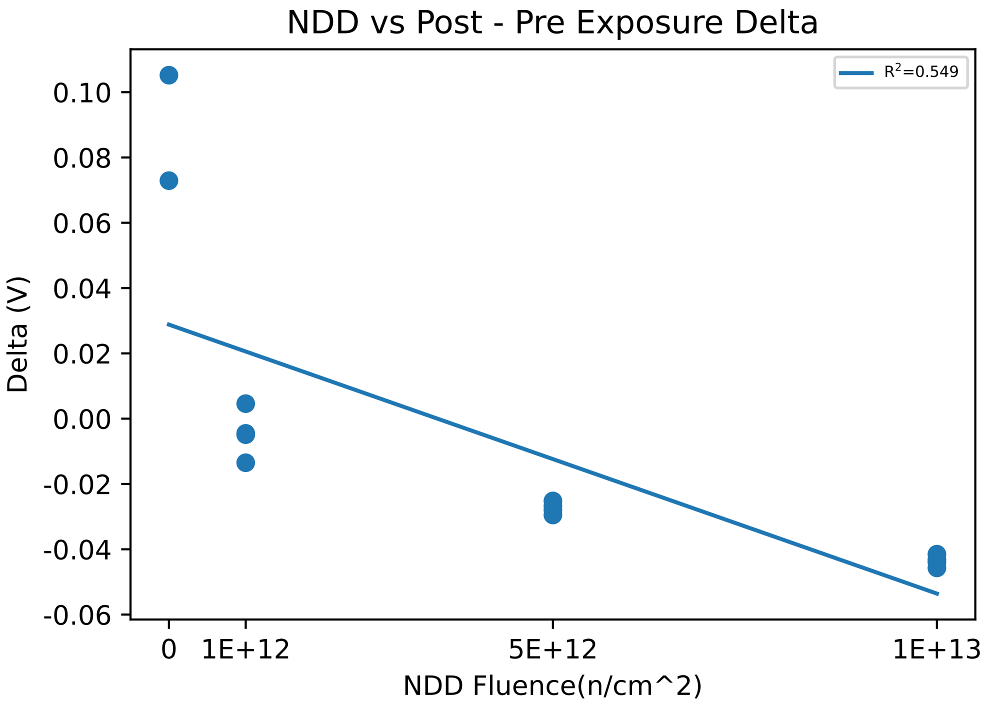
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	4.997	4.9879	-0.0091
2	0	Correlation	5.0224	5.0171	-0.0053
30	1e+12	NDD unbiased	4.9902	4.9891	-0.0011
31	1e+12	NDD unbiased	4.9935	4.9867	-0.0068
32	1e+12	NDD unbiased	5.0121	5.0088	-0.0033
33	1e+12	NDD unbiased	5.0094	5.0067	-0.0027
44	5e+12	NDD unbiased	4.9991	4.9812	-0.0179
45	5e+12	NDD unbiased	4.987	4.9979	0.0109
46	5e+12	NDD unbiased	4.9866	4.9677	-0.0189
47	5e+12	NDD unbiased	5.016	4.9976	-0.0184
50	1e+13	NDD unbiased	5.0165	4.9832	-0.0333
51	1e+13	NDD unbiased	4.989	4.9528	-0.0362
52	1e+13	NDD unbiased	5.0003	4.971	-0.0293
53	1e+13	NDD unbiased	4.9907	4.956	-0.0347

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.997	5.0097	5.0224	0.017961	4.9879	5.0025	5.0171	0.020648	-0.0091	-0.0072	-0.0053	0.002687
1e+12	4.9902	5.0013	5.0121	0.01105	4.9867	4.9978	5.0088	0.011534	-0.0068	-0.003475	-0.0011	0.0024033
5e+12	4.9866	4.9972	5.016	0.013826	4.9677	4.9861	4.9979	0.014538	-0.0189	-0.011075	0.0109	0.014656
1e+13	4.989	4.9991	5.0165	0.012606	4.9528	4.9657	4.9832	0.014081	-0.0362	-0.033375	-0.0293	0.0029635

Device Test: 62.15 V_BP7L(_V_BP7L IIM 1MHz VIN_14V)


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

Test Results (Lower Limit = 6.65, Upper Limit = 7.35 (V))

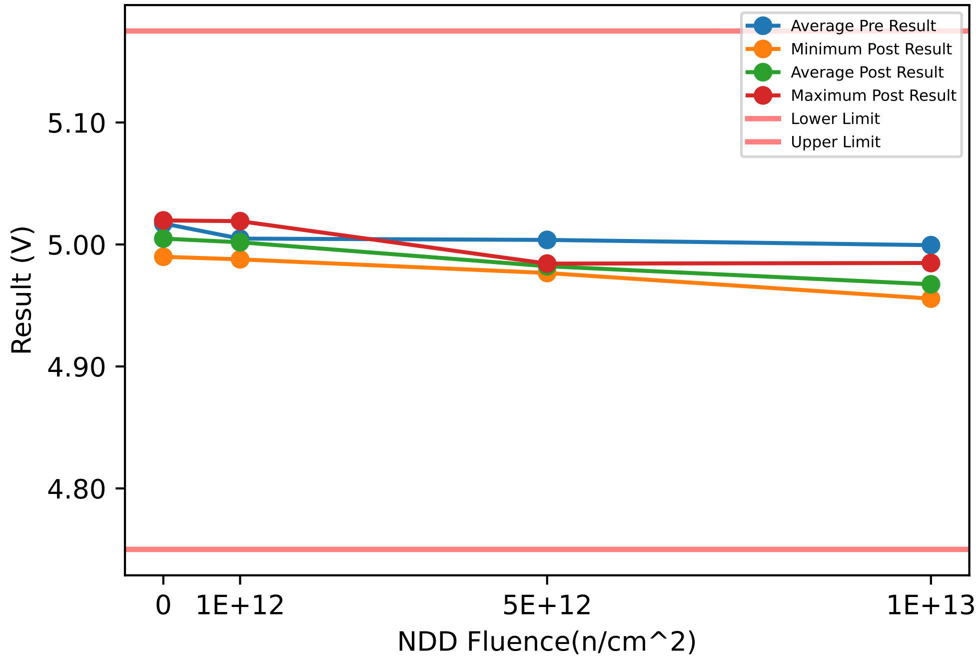
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	7.0018	7.0747	0.0729
2	0	Correlation	6.9944	7.0996	0.1052
30	1e+12	NDD unbiased	7.0298	7.0344	0.0046
31	1e+12	NDD unbiased	7.0388	7.0253	-0.0135
32	1e+12	NDD unbiased	6.9932	6.9883	-0.0049
33	1e+12	NDD unbiased	7.0103	7.0058	-0.0045
44	5e+12	NDD unbiased	7.0488	7.0236	-0.0252
45	5e+12	NDD unbiased	7.0388	7.0093	-0.0295
46	5e+12	NDD unbiased	7.092	7.0653	-0.0267
47	5e+12	NDD unbiased	7.037	7.009	-0.028
50	1e+13	NDD unbiased	6.9563	6.9148	-0.0415
51	1e+13	NDD unbiased	6.9584	6.9144	-0.044
52	1e+13	NDD unbiased	6.9585	6.9154	-0.0431
53	1e+13	NDD unbiased	7.0074	6.9617	-0.0457

Test Statistics (V)

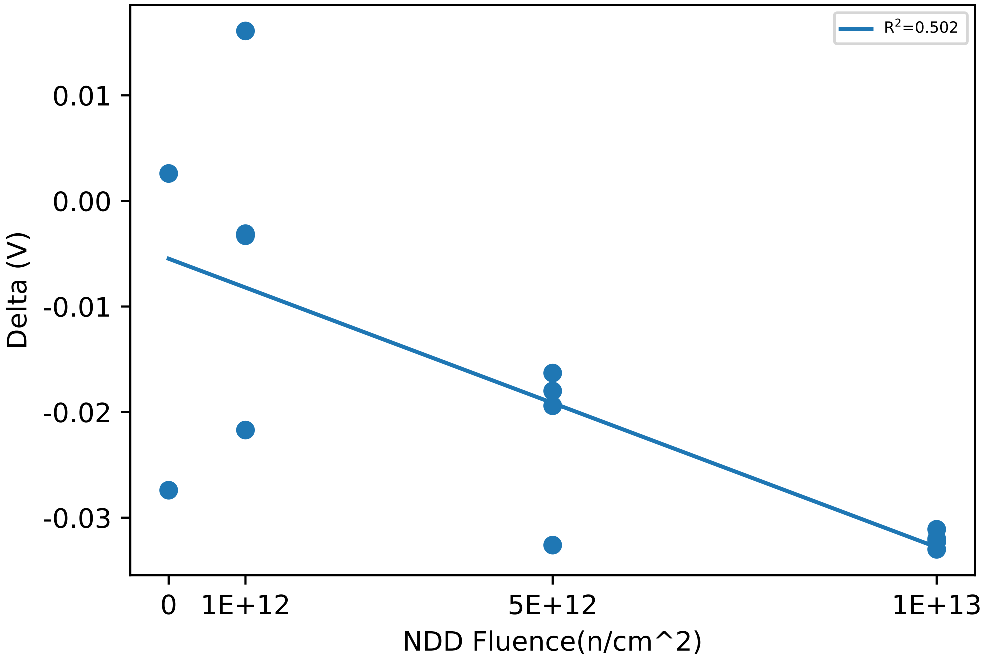
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	6.9944	6.9981	7.0018	0.0052326	7.0747	7.0871	7.0996	0.017607	0.0729	0.08905	0.1052	0.02284
1e+12	6.9932	7.018	7.0388	0.020381	6.9883	7.0134	7.0344	0.020578	-0.0135	-0.004575	0.0046	0.0073925
5e+12	7.037	7.0541	7.092	0.025762	7.009	7.0268	7.0653	0.026555	-0.0295	-0.02735	-0.0252	0.0018339
1e+13	6.9563	6.9702	7.0074	0.024854	6.9144	6.9266	6.9617	0.02342	-0.0457	-0.043575	-0.0415	0.0017538

Device Test: 62.16 V_BP5L(_V_BP5L IIM 1MHz VIN_14V)

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



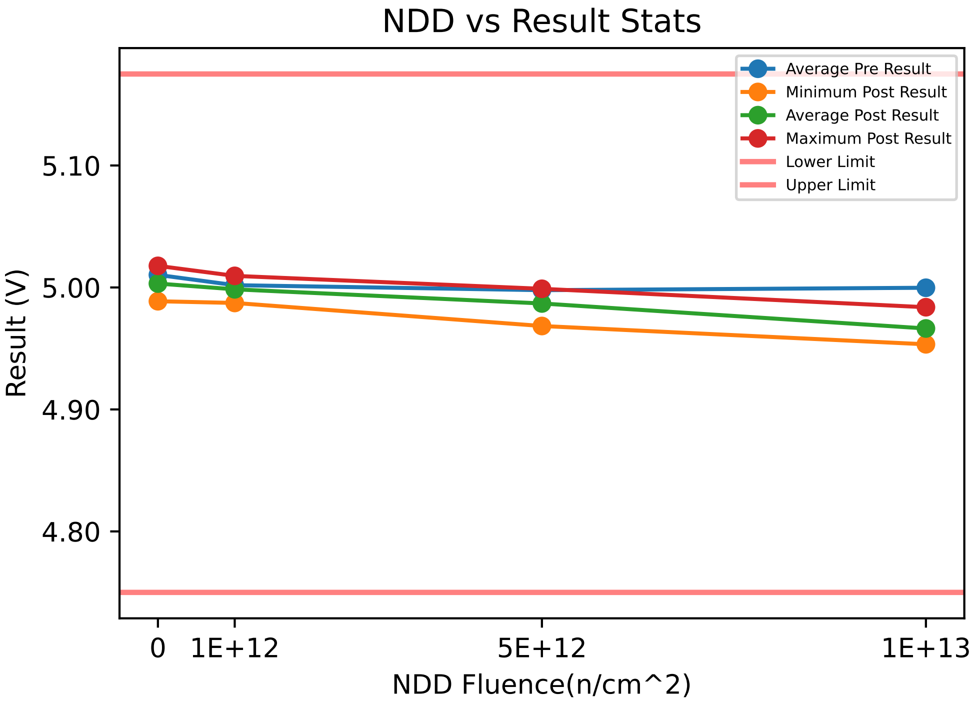
Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

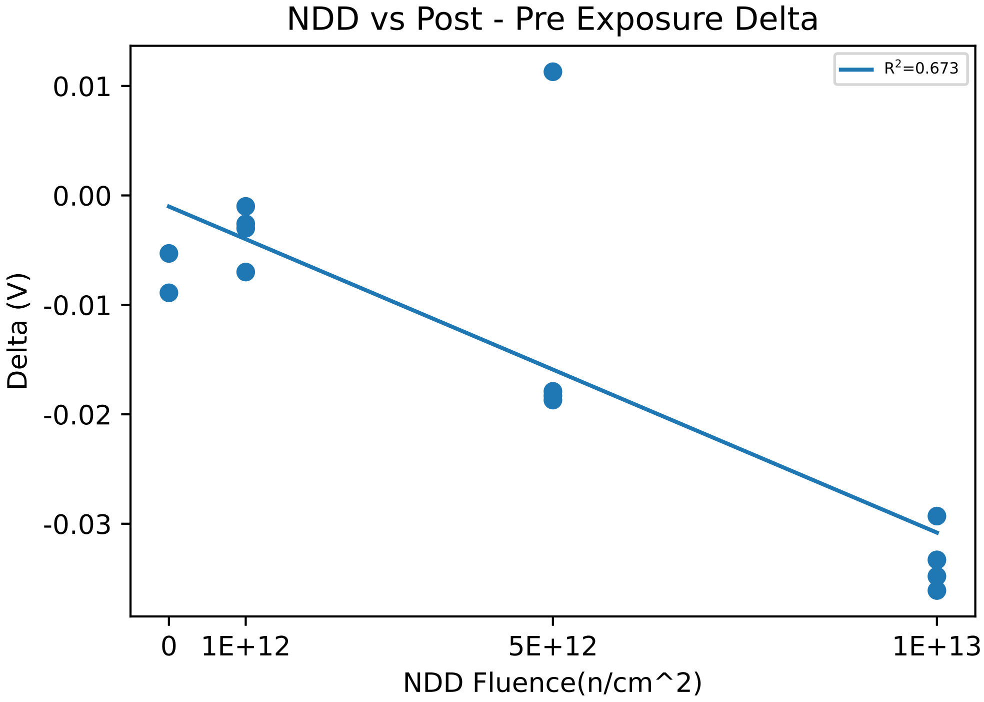
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	5.0173	4.9899	-0.0274
2	0	Correlation	5.0171	5.0197	0.0026
30	1e+12	NDD unbiased	5.0223	5.0006	-0.0217
31	1e+12	NDD unbiased	5.003	5.0191	0.0161
32	1e+12	NDD unbiased	5.0028	4.9997	-0.0031
33	1e+12	NDD unbiased	4.9911	4.9878	-0.0033
44	5e+12	NDD unbiased	4.9929	4.9766	-0.0163
45	5e+12	NDD unbiased	5.0169	4.9843	-0.0326
46	5e+12	NDD unbiased	5.0015	4.9835	-0.018
47	5e+12	NDD unbiased	5.0036	4.9842	-0.0194
50	1e+13	NDD unbiased	4.9876	4.9556	-0.032
51	1e+13	NDD unbiased	4.9996	4.9673	-0.0323
52	1e+13	NDD unbiased	5.0159	4.9848	-0.0311
53	1e+13	NDD unbiased	4.9946	4.9616	-0.033

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.0171	5.0172	5.0173	0.00014142	4.9899	5.0048	5.0197	0.021072	-0.0274	-0.0124	0.0026	0.021213
1e+12	4.9911	5.0048	5.0223	0.012925	4.9878	5.0018	5.0191	0.012925	-0.0217	-0.003	0.0161	0.015434
5e+12	4.9929	5.0037	5.0169	0.0099285	4.9766	4.9822	4.9843	0.0037171	-0.0326	-0.021575	-0.0163	0.0074585
1e+13	4.9876	4.9994	5.0159	0.012036	4.9556	4.9673	4.9848	0.012591	-0.033	-0.0321	-0.0311	0.0007874

Device Test: 62.17 V_BP5H(_V_BP5H IIM 1MHz VIN_14V)





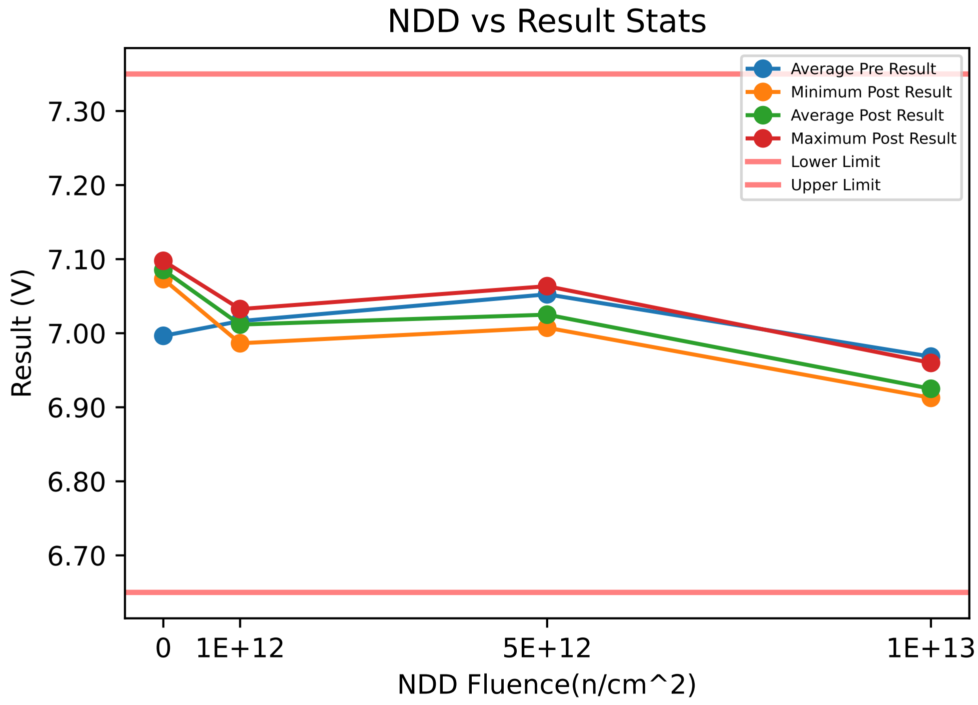
Test Results (Lower Limit = 4.75,
Upper Limit = 5.175 (V))

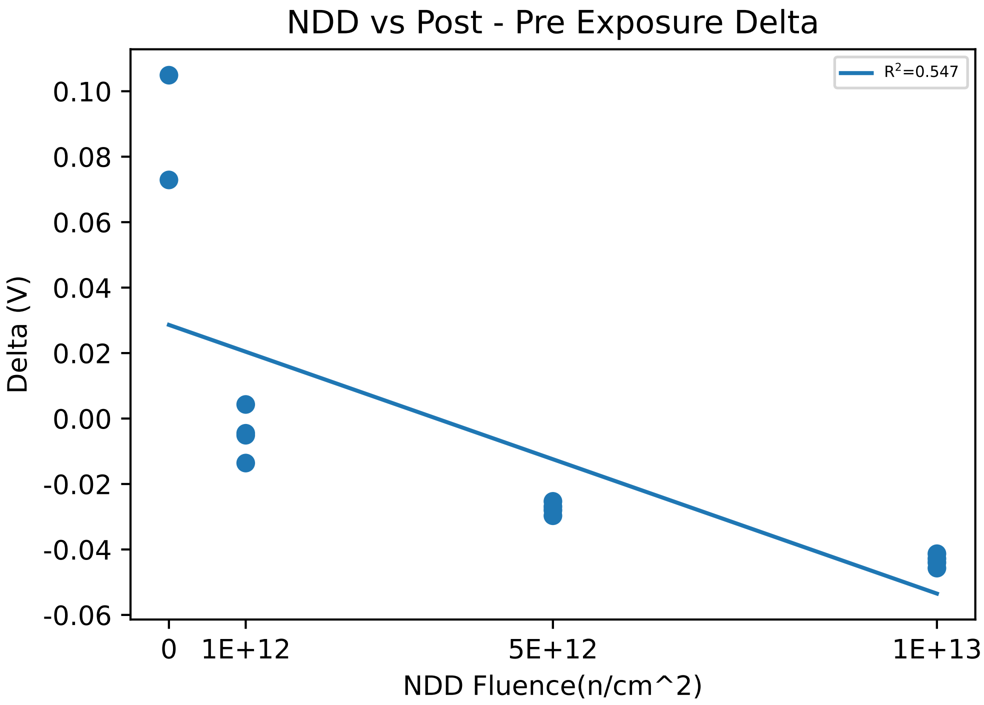
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	4.9976	4.9887	-0.0089
2	0	Correlation	5.023	5.0177	-0.0053
30	1e+12	NDD unbiased	4.9908	4.9898	-0.001
31	1e+12	NDD unbiased	4.9943	4.9873	-0.007
32	1e+12	NDD unbiased	5.0125	5.0095	-0.003
33	1e+12	NDD unbiased	5.0099	5.0073	-0.0026
44	5e+12	NDD unbiased	4.9997	4.9818	-0.0179
45	5e+12	NDD unbiased	4.9876	4.9989	0.0113
46	5e+12	NDD unbiased	4.9871	4.9684	-0.0187
47	5e+12	NDD unbiased	5.0167	4.9984	-0.0183
50	1e+13	NDD unbiased	5.0171	4.9838	-0.0333
51	1e+13	NDD unbiased	4.9895	4.9534	-0.0361
52	1e+13	NDD unbiased	5.001	4.9717	-0.0293
53	1e+13	NDD unbiased	4.9914	4.9566	-0.0348

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.9976	5.0103	5.023	0.017961	4.9887	5.0032	5.0177	0.020506	-0.0089	-0.0071	-0.0053	0.0025456
1e+12	4.9908	5.0019	5.0125	0.010914	4.9873	4.9985	5.0095	0.011541	-0.007	-0.0034	-0.001	0.0025508
5e+12	4.9871	4.9978	5.0167	0.013897	4.9684	4.9869	4.9989	0.014657	-0.0187	-0.0109	0.0113	0.014804
1e+13	4.9895	4.9997	5.0171	0.012614	4.9534	4.9664	4.9838	0.014094	-0.0361	-0.033375	-0.0293	0.0029477

Device Test: 62.18 V_BP7L(_V_BP7L IIM 2MHz VIN_14V)


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

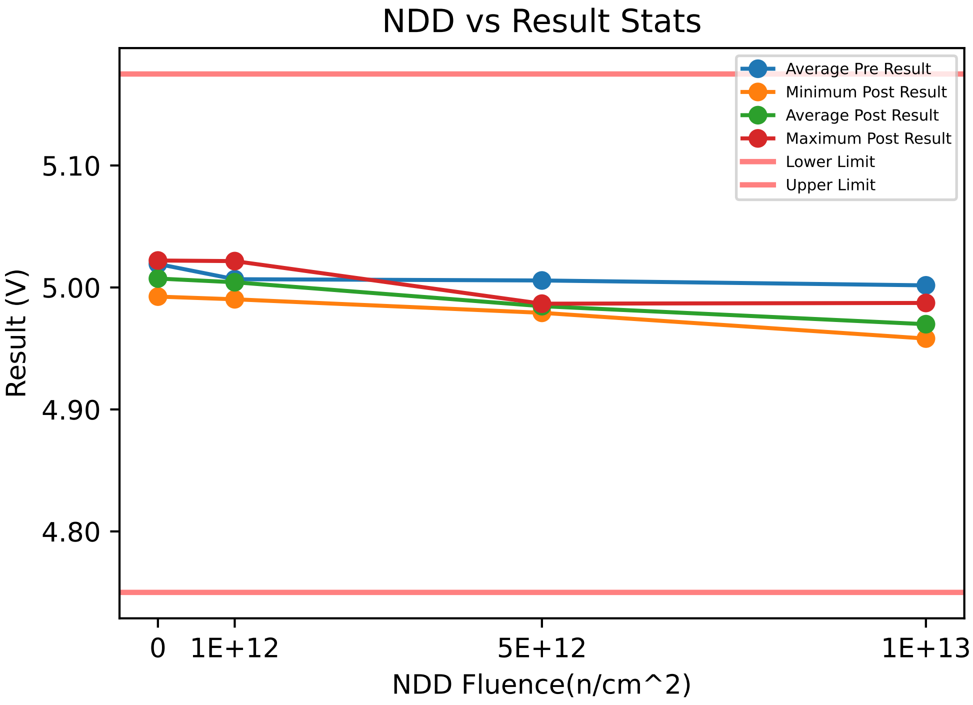
Test Results (Lower Limit = 6.65, Upper Limit = 7.35 (V))

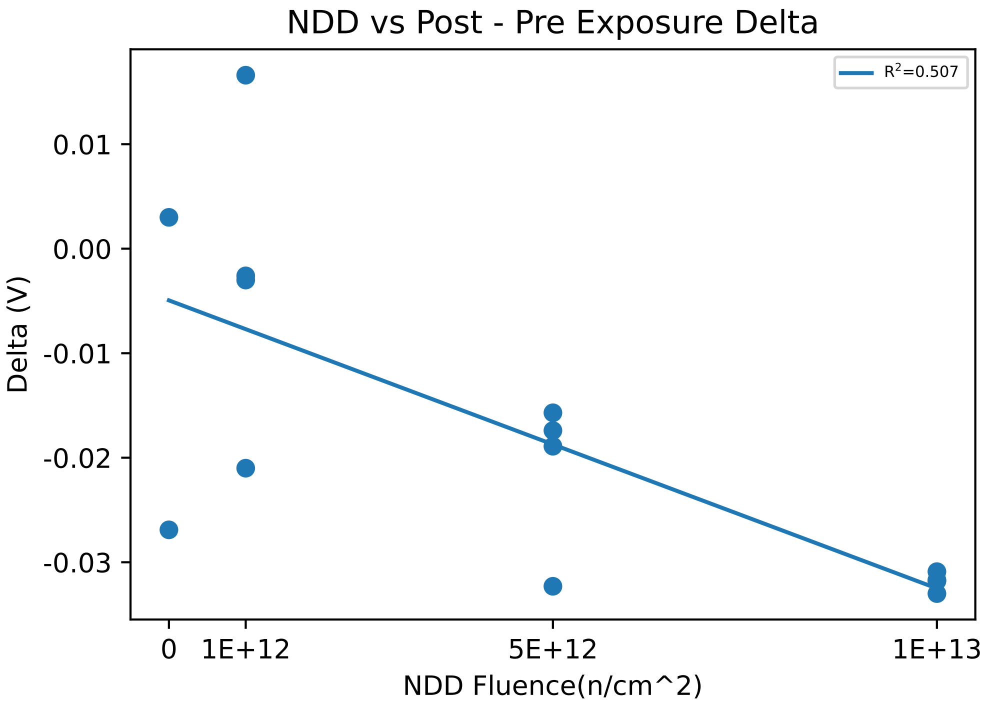
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	7.0001	7.073	0.0729
2	0	Correlation	6.9928	7.0977	0.1049
30	1e+12	NDD unbiased	7.0283	7.0326	0.0043
31	1e+12	NDD unbiased	7.0372	7.0236	-0.0136
32	1e+12	NDD unbiased	6.9915	6.9864	-0.0051
33	1e+12	NDD unbiased	7.0084	7.0039	-0.0045
44	5e+12	NDD unbiased	7.047	7.0217	-0.0253
45	5e+12	NDD unbiased	7.0372	7.0075	-0.0297
46	5e+12	NDD unbiased	7.0904	7.0635	-0.0269
47	5e+12	NDD unbiased	7.0354	7.0074	-0.028
50	1e+13	NDD unbiased	6.9546	6.9133	-0.0413
51	1e+13	NDD unbiased	6.9567	6.9127	-0.044
52	1e+13	NDD unbiased	6.9567	6.9139	-0.0428
53	1e+13	NDD unbiased	7.0056	6.9599	-0.0457

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	6.9928	6.9964	7.0001	0.0051619	7.073	7.0854	7.0977	0.017466	0.0729	0.0889	0.1049	0.022627
1e+12	6.9915	7.0164	7.0372	0.02048	6.9864	7.0116	7.0326	0.02065	-0.0136	-0.004725	0.0043	0.0073123
5e+12	7.0354	7.0525	7.0904	0.025776	7.0074	7.025	7.0635	0.026515	-0.0297	-0.027475	-0.0253	0.0018518
1e+13	6.9546	6.9684	7.0056	0.02482	6.9127	6.9249	6.9599	0.023305	-0.0457	-0.04345	-0.0413	0.0018628

Device Test: 62.19 V_BP5L(_V_BP5L IIM 2MHz VIN_14V)





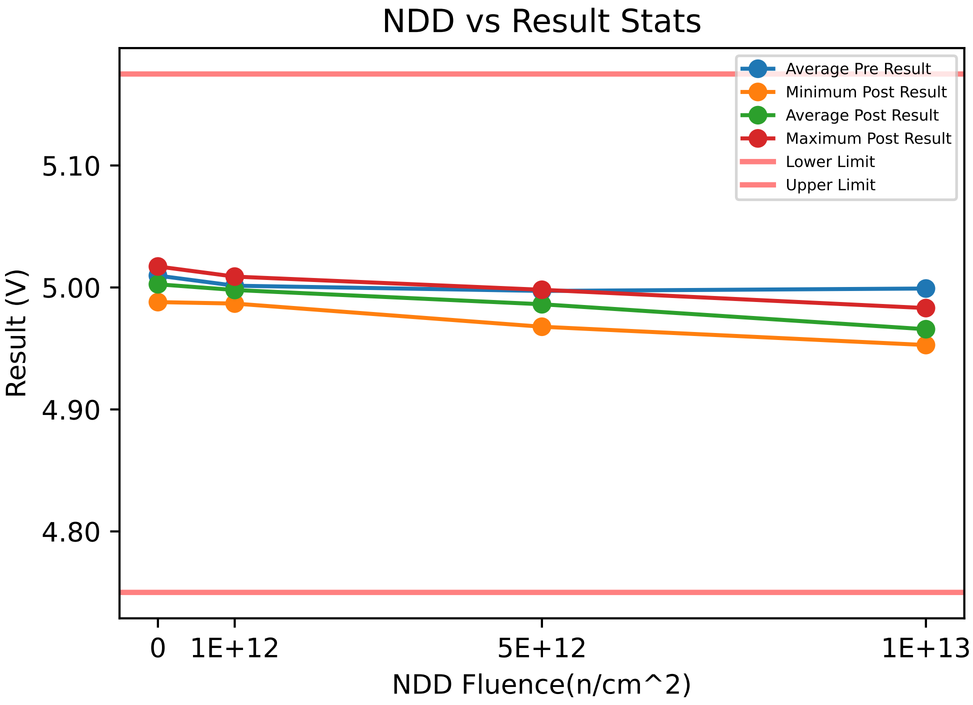
Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

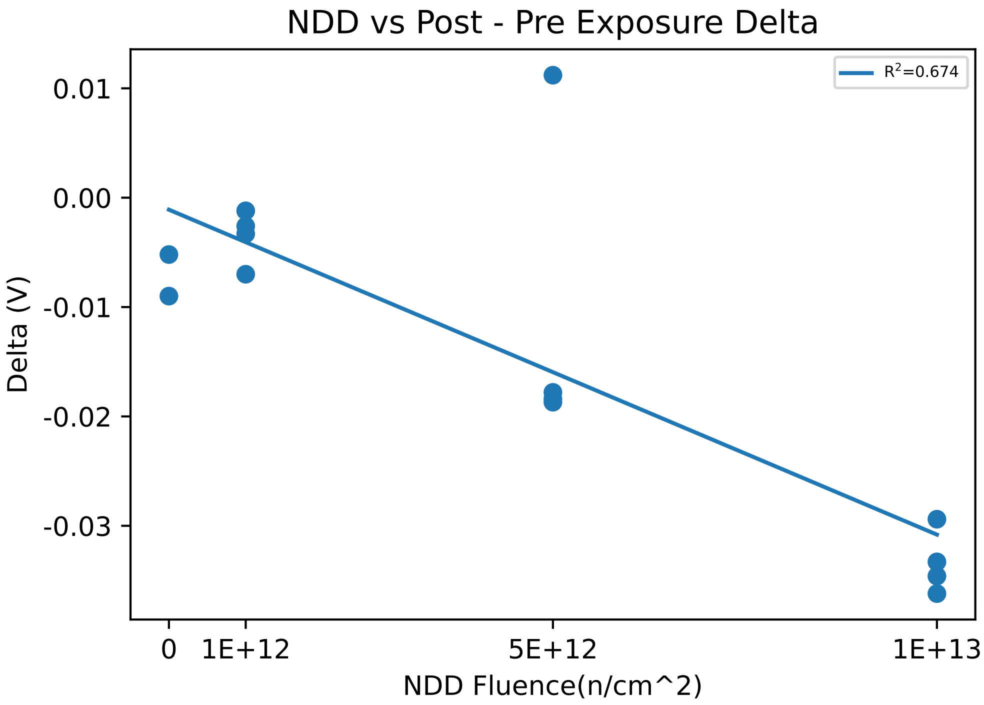
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	5.0194	4.9925	-0.0269
2	0	Correlation	5.0191	5.0221	0.003
30	1e+12	NDD unbiased	5.0241	5.0031	-0.021
31	1e+12	NDD unbiased	5.005	5.0216	0.0166
32	1e+12	NDD unbiased	5.0047	5.0021	-0.0026
33	1e+12	NDD unbiased	4.9933	4.9903	-0.003
44	5e+12	NDD unbiased	4.9949	4.9792	-0.0157
45	5e+12	NDD unbiased	5.019	4.9867	-0.0323
46	5e+12	NDD unbiased	5.0035	4.9861	-0.0174
47	5e+12	NDD unbiased	5.0055	4.9866	-0.0189
50	1e+13	NDD unbiased	4.9899	4.9581	-0.0318
51	1e+13	NDD unbiased	5.0018	4.9701	-0.0317
52	1e+13	NDD unbiased	5.0182	4.9873	-0.0309
53	1e+13	NDD unbiased	4.997	4.964	-0.033

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.0191	5.0192	5.0194	0.00021213	4.9925	5.0073	5.0221	0.02093	-0.0269	-0.01195	0.003	0.021142
1e+12	4.9933	5.0068	5.0241	0.01277	4.9903	5.0043	5.0216	0.01293	-0.021	-0.0025	0.0166	0.015355
5e+12	4.9949	5.0057	5.019	0.0099734	4.9792	4.9847	4.9867	0.0036428	-0.0323	-0.021075	-0.0157	0.0075967
1e+13	4.9899	5.0017	5.0182	0.012022	4.9581	4.9699	4.9873	0.012608	-0.033	-0.03185	-0.0309	0.00086603

Device Test: 62.2 V_BP5H(_V_BP5H PWM 500kHz VIN_14V)





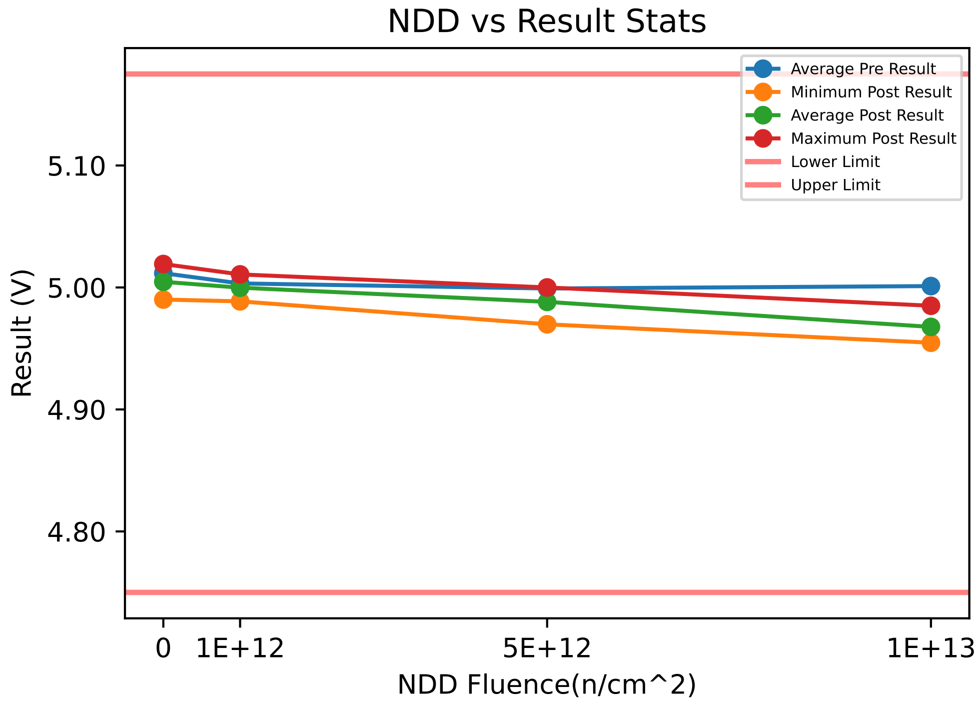
Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

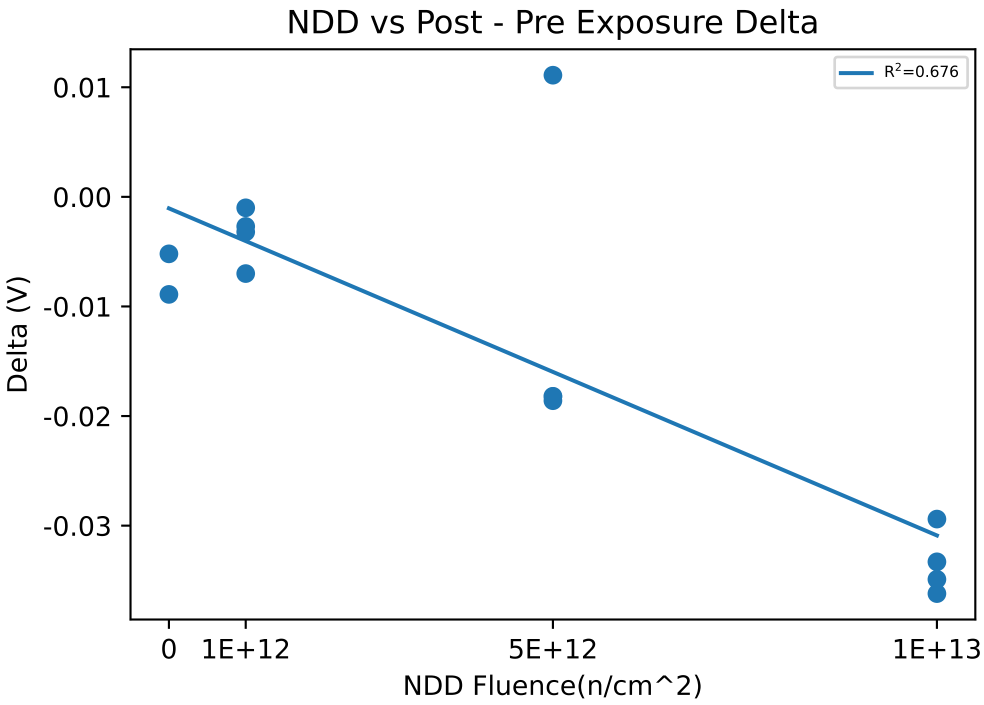
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	4.997	4.988	-0.009
2	0	Correlation	5.0224	5.0172	-0.0052
30	1e+12	NDD unbiased	4.9904	4.9892	-0.0012
31	1e+12	NDD unbiased	4.9938	4.9868	-0.007
32	1e+12	NDD unbiased	5.0122	5.0089	-0.0033
33	1e+12	NDD unbiased	5.0094	5.0068	-0.0026
44	5e+12	NDD unbiased	4.9991	4.9813	-0.0178
45	5e+12	NDD unbiased	4.9869	4.9981	0.0112
46	5e+12	NDD unbiased	4.9865	4.9678	-0.0187
47	5e+12	NDD unbiased	5.0161	4.9977	-0.0184
50	1e+13	NDD unbiased	5.0164	4.9831	-0.0333
51	1e+13	NDD unbiased	4.989	4.9528	-0.0362
52	1e+13	NDD unbiased	5.0004	4.971	-0.0294
53	1e+13	NDD unbiased	4.9907	4.9561	-0.0346

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.997	5.0097	5.0224	0.017961	4.988	5.0026	5.0172	0.020648	-0.009	-0.0071	-0.0052	0.002687
1e+12	4.9904	5.0015	5.0122	0.010945	4.9868	4.9979	5.0089	0.011534	-0.007	-0.003525	-0.0012	0.0024757
5e+12	4.9865	4.9972	5.0161	0.013921	4.9678	4.9862	4.9981	0.014565	-0.0187	-0.010925	0.0112	0.014755
1e+13	4.989	4.9991	5.0164	0.012564	4.9528	4.9657	4.9831	0.014017	-0.0362	-0.033375	-0.0294	0.0029033

Device Test: 62.20 V_BP5H(_V_BP5H IIM 2MHz VIN_14V)





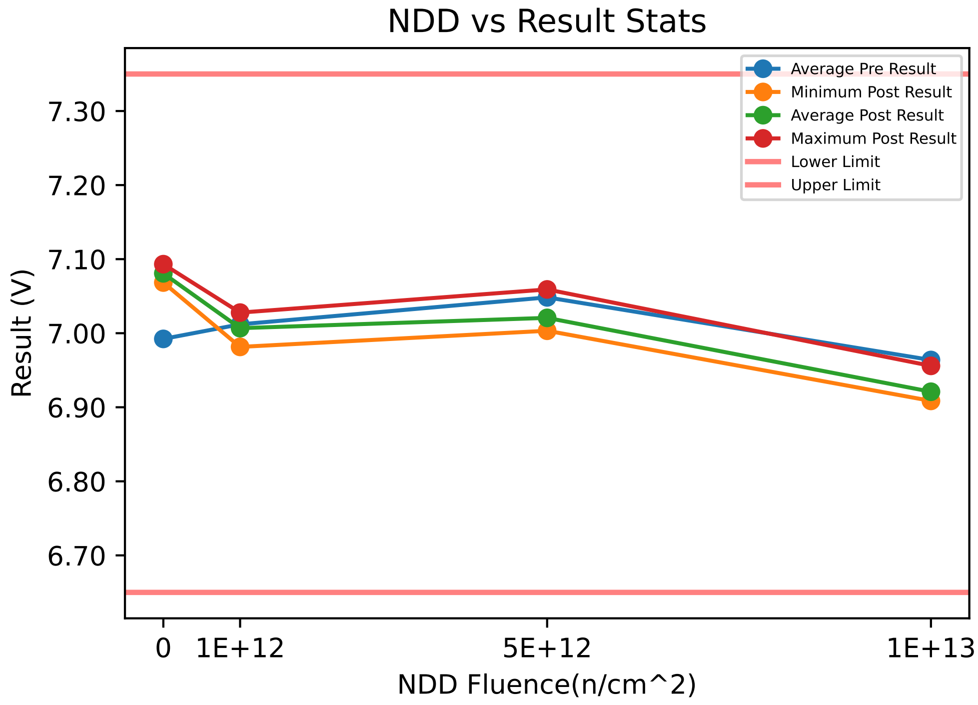
Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

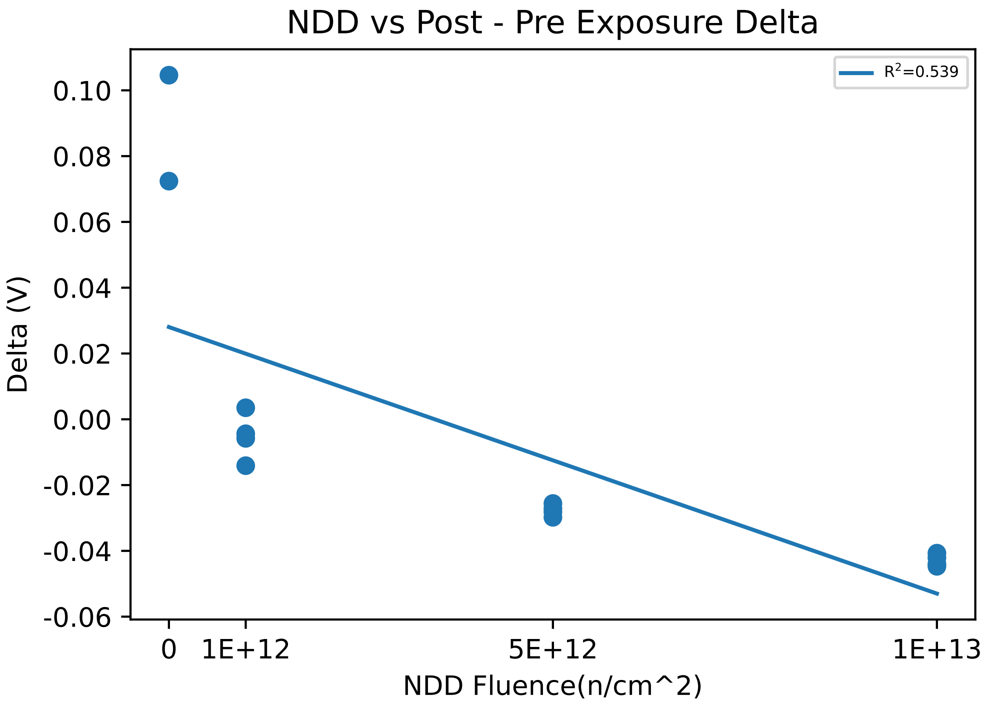
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	4.999	4.9901	-0.0089
2	0	Correlation	5.0244	5.0192	-0.0052
30	1e+12	NDD unbiased	4.9923	4.9913	-0.001
31	1e+12	NDD unbiased	4.9956	4.9886	-0.007
32	1e+12	NDD unbiased	5.0139	5.0107	-0.0032
33	1e+12	NDD unbiased	5.0114	5.0087	-0.0027
44	5e+12	NDD unbiased	5.0013	4.9831	-0.0182
45	5e+12	NDD unbiased	4.9889	5	0.0111
46	5e+12	NDD unbiased	4.9884	4.9698	-0.0186
47	5e+12	NDD unbiased	5.018	4.9998	-0.0182
50	1e+13	NDD unbiased	5.0183	4.985	-0.0333
51	1e+13	NDD unbiased	4.9909	4.9547	-0.0362
52	1e+13	NDD unbiased	5.0023	4.9729	-0.0294
53	1e+13	NDD unbiased	4.993	4.9581	-0.0349

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.999	5.0117	5.0244	0.017961	4.9901	5.0046	5.0192	0.020577	-0.0089	-0.00705	-0.0052	0.0026163
1e+12	4.9923	5.0033	5.0139	0.010928	4.9886	4.9998	5.0107	0.011485	-0.007	-0.003475	-0.001	0.0025316
5e+12	4.9884	4.9992	5.018	0.013911	4.9698	4.9882	5	0.014587	-0.0186	-0.010975	0.0111	0.014718
1e+13	4.9909	5.0011	5.0183	0.012476	4.9547	4.9677	4.985	0.013994	-0.0362	-0.03345	-0.0294	0.002949

Device Test: 62.21 V_BP7L(_V_BP7L IIM 5MHz VIN_14V)





Test Results (Lower Limit = 6.65, Upper Limit = 7.35 (V))

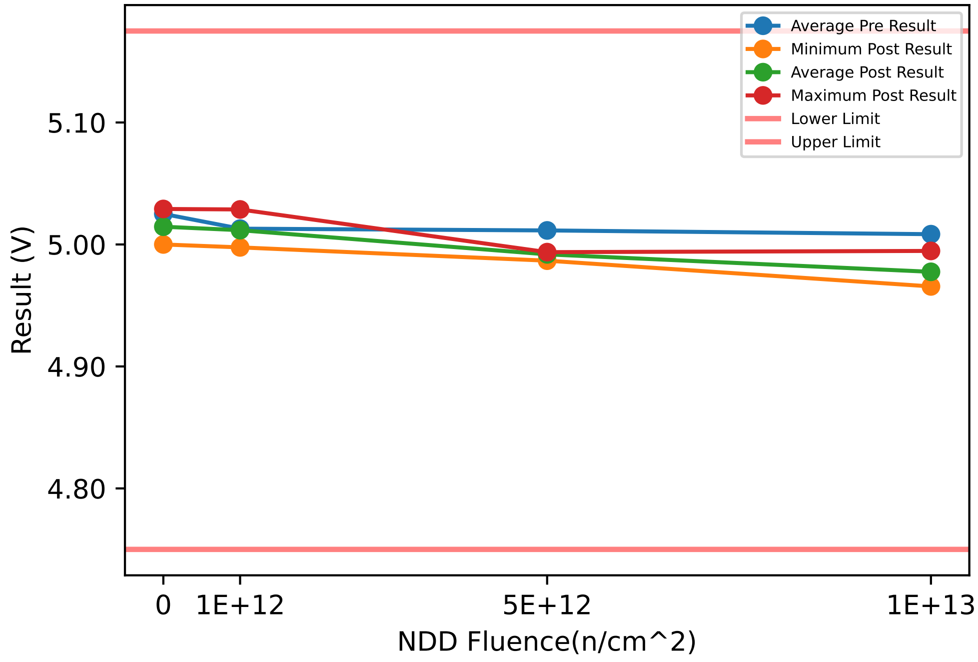
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	6.996	7.0684	0.0724
2	0	Correlation	6.9886	7.0932	0.1046
30	1e+12	NDD unbiased	7.0243	7.0278	0.0035
31	1e+12	NDD unbiased	7.0333	7.0192	-0.0141
32	1e+12	NDD unbiased	6.9873	6.9815	-0.0058
33	1e+12	NDD unbiased	7.0031	6.9987	-0.0044
44	5e+12	NDD unbiased	7.0427	7.0171	-0.0256
45	5e+12	NDD unbiased	7.0331	7.0033	-0.0298
46	5e+12	NDD unbiased	7.0862	7.0591	-0.0271
47	5e+12	NDD unbiased	7.0315	7.0033	-0.0282
50	1e+13	NDD unbiased	6.9499	6.9092	-0.0407
51	1e+13	NDD unbiased	6.9526	6.9086	-0.044
52	1e+13	NDD unbiased	6.9522	6.9101	-0.0421
53	1e+13	NDD unbiased	7.0006	6.9559	-0.0447

Test Statistics (V)

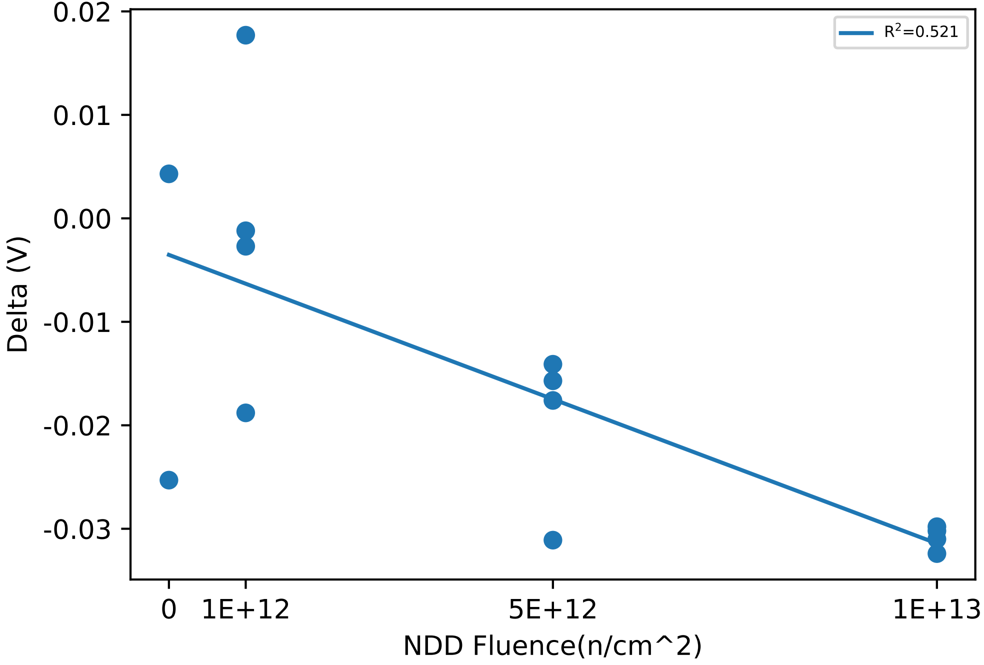
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	6.9886	6.9923	6.996	0.0052326	7.0684	7.0808	7.0932	0.017536	0.0724	0.0885	0.1046	0.022769
1e+12	6.9873	7.012	7.0333	0.020771	6.9815	7.0068	7.0278	0.02082	-0.0141	-0.0052	0.0035	0.0072088
5e+12	7.0315	7.0484	7.0862	0.025697	7.0033	7.0207	7.0591	0.026414	-0.0298	-0.027675	-0.0256	0.0017727
1e+13	6.9499	6.9638	7.0006	0.024546	6.9086	6.9209	6.9559	0.023308	-0.0447	-0.042875	-0.0407	0.0018191

Device Test: 62.22 V_BP5L(_V_BP5L IIM 5MHz VIN_14V)

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



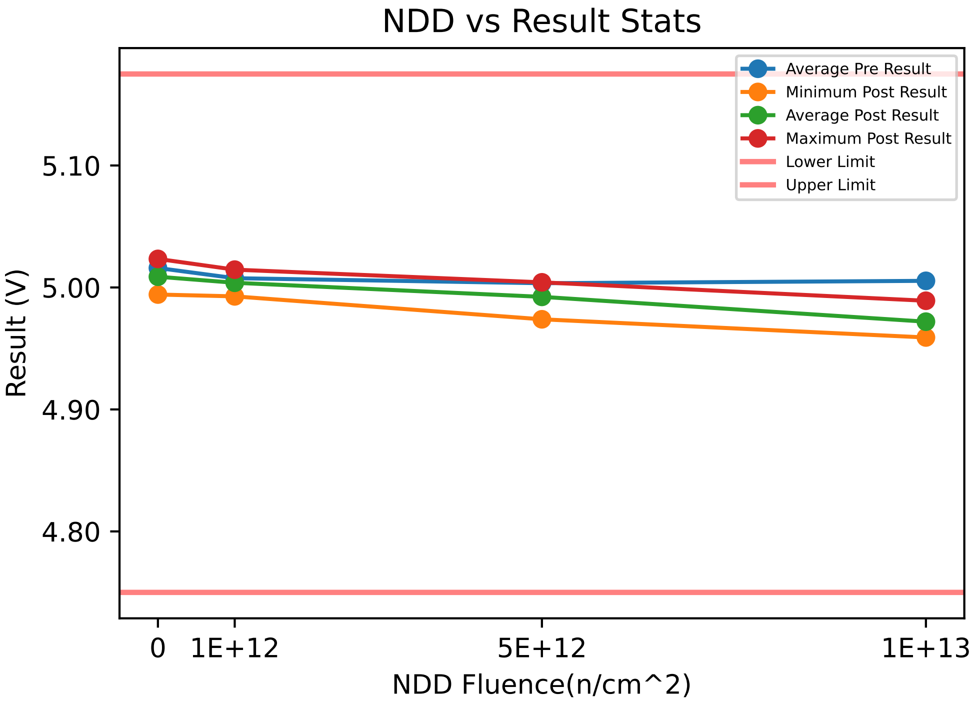
Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

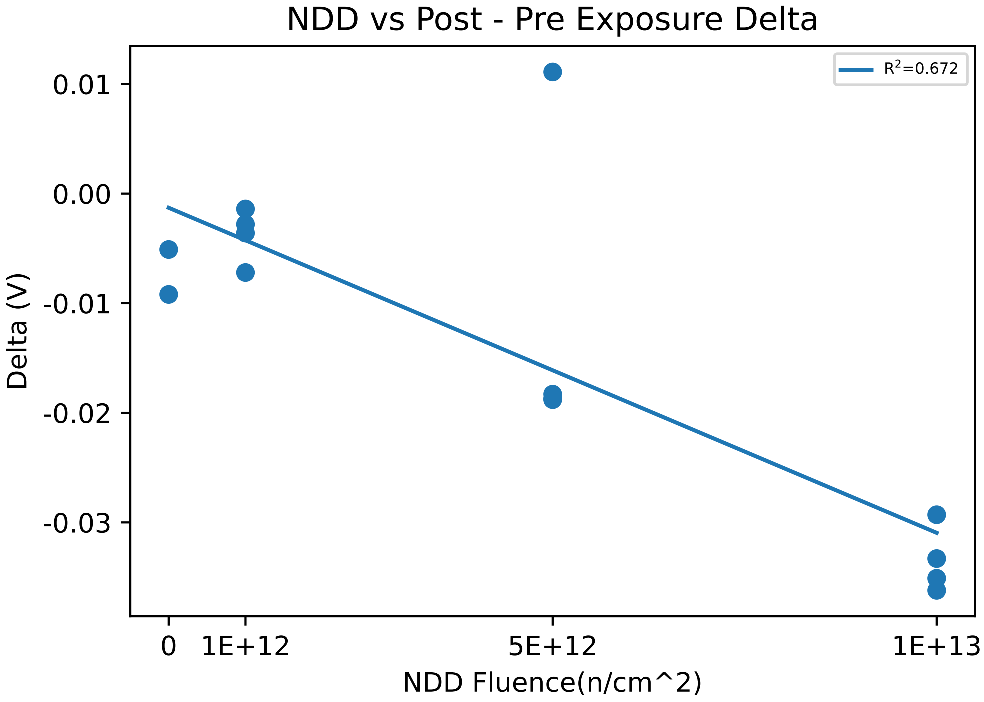
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	5.0253	5	-0.0253
2	0	Correlation	5.0248	5.0291	0.0043
30	1e+12	NDD unbiased	5.0299	5.0111	-0.0188
31	1e+12	NDD unbiased	5.011	5.0287	0.0177
32	1e+12	NDD unbiased	5.0106	5.0094	-0.0012
33	1e+12	NDD unbiased	5.0003	4.9976	-0.0027
44	5e+12	NDD unbiased	5.0008	4.9867	-0.0141
45	5e+12	NDD unbiased	5.0248	4.9937	-0.0311
46	5e+12	NDD unbiased	5.0093	4.9936	-0.0157
47	5e+12	NDD unbiased	5.0111	4.9935	-0.0176
50	1e+13	NDD unbiased	4.9966	4.9656	-0.031
51	1e+13	NDD unbiased	5.0083	4.9785	-0.0298
52	1e+13	NDD unbiased	5.0249	4.9947	-0.0302
53	1e+13	NDD unbiased	5.0039	4.9715	-0.0324

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.0248	5.0251	5.0253	0.00035355	5	5.0145	5.0291	0.020577	-0.0253	-0.0105	0.0043	0.02093
1e+12	5.0003	5.013	5.0299	0.012338	4.9976	5.0117	5.0287	0.012825	-0.0188	-0.00125	0.0177	0.014936
5e+12	5.0008	5.0115	5.0248	0.0099395	4.9867	4.9919	4.9937	0.003451	-0.0311	-0.019625	-0.0141	0.0077826
1e+13	4.9966	5.0084	5.0249	0.011996	4.9656	4.9776	4.9947	0.012575	-0.0324	-0.03085	-0.0298	0.0011475

Device Test: 62.23 V_BP5H(_V_BP5H IIM 5MHz VIN_14V)


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

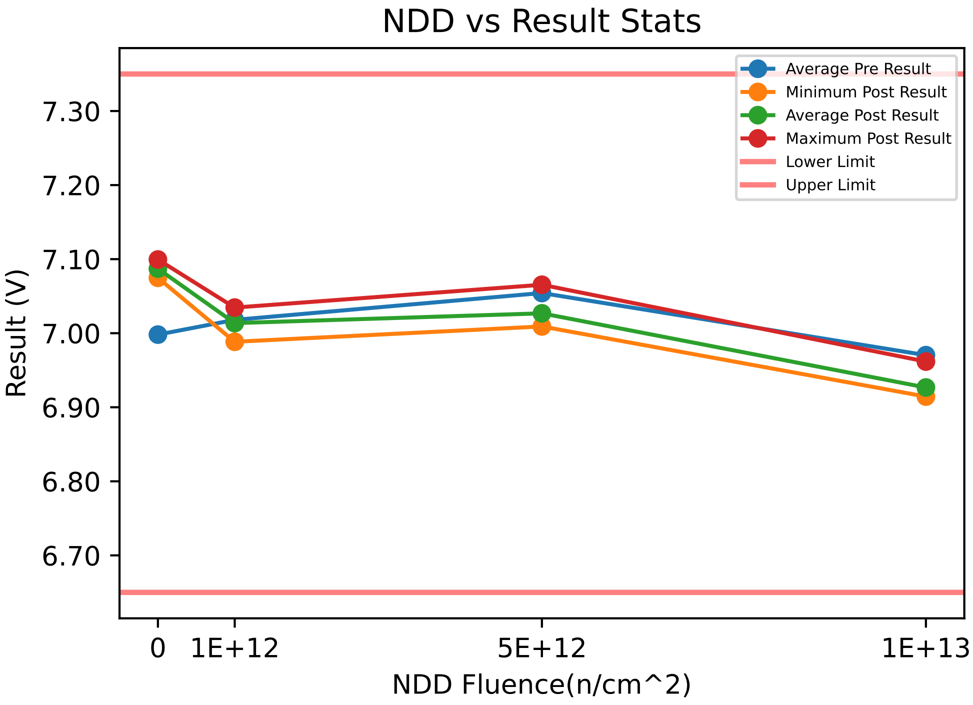
Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

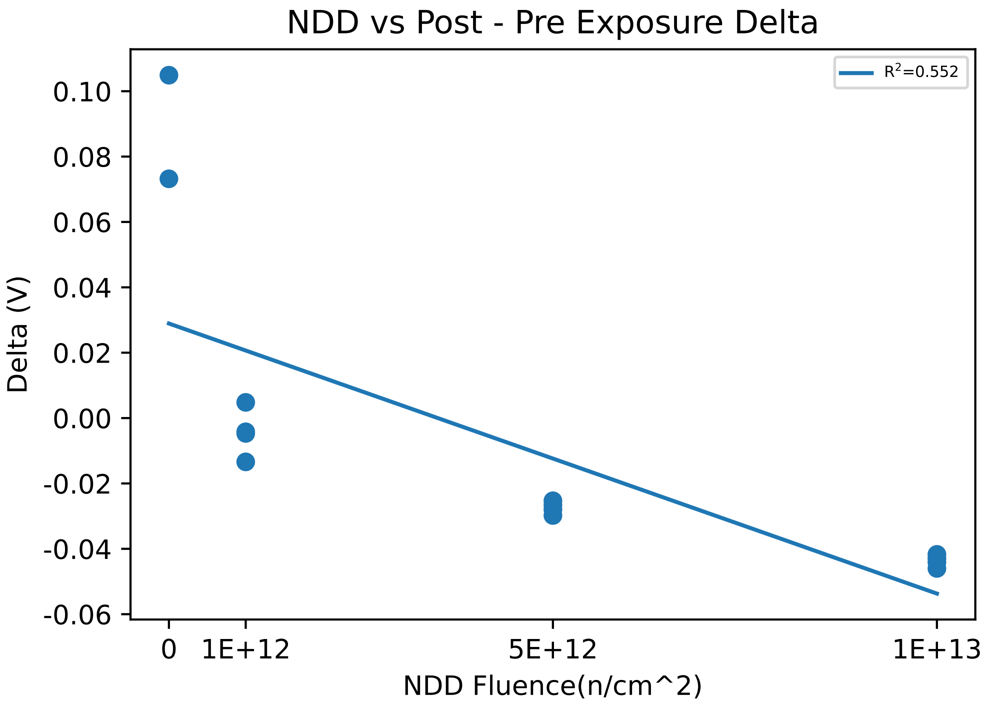
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	5.0034	4.9942	-0.0092
2	0	Correlation	5.0285	5.0234	-0.0051
30	1e+12	NDD unbiased	4.9966	4.9952	-0.0014
31	1e+12	NDD unbiased	4.9999	4.9927	-0.0072
32	1e+12	NDD unbiased	5.0182	5.0146	-0.0036
33	1e+12	NDD unbiased	5.0157	5.0129	-0.0028
44	5e+12	NDD unbiased	5.0057	4.9874	-0.0183
45	5e+12	NDD unbiased	4.9931	5.0042	0.0111
46	5e+12	NDD unbiased	4.9927	4.9739	-0.0188
47	5e+12	NDD unbiased	5.0224	5.0037	-0.0187
50	1e+13	NDD unbiased	5.0224	4.9891	-0.0333
51	1e+13	NDD unbiased	4.9952	4.959	-0.0362
52	1e+13	NDD unbiased	5.0066	4.9773	-0.0293
53	1e+13	NDD unbiased	4.9975	4.9624	-0.0351

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.0034	5.016	5.0285	0.017748	4.9942	5.0088	5.0234	0.020648	-0.0092	-0.00715	-0.0051	0.0028991
1e+12	4.9966	5.0076	5.0182	0.010928	4.9927	5.0038	5.0146	0.011498	-0.0072	-0.00375	-0.0014	0.0024732
5e+12	4.9927	5.0035	5.0224	0.013986	4.9739	4.9923	5.0042	0.014539	-0.0188	-0.011175	0.0111	0.014852
1e+13	4.9952	5.0054	5.0224	0.012341	4.959	4.9719	4.9891	0.013924	-0.0362	-0.033475	-0.0293	0.0030292

Device Test: 62.3 V_BP7L(_V_BP7L PWM 1MHz VIN_14V)


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

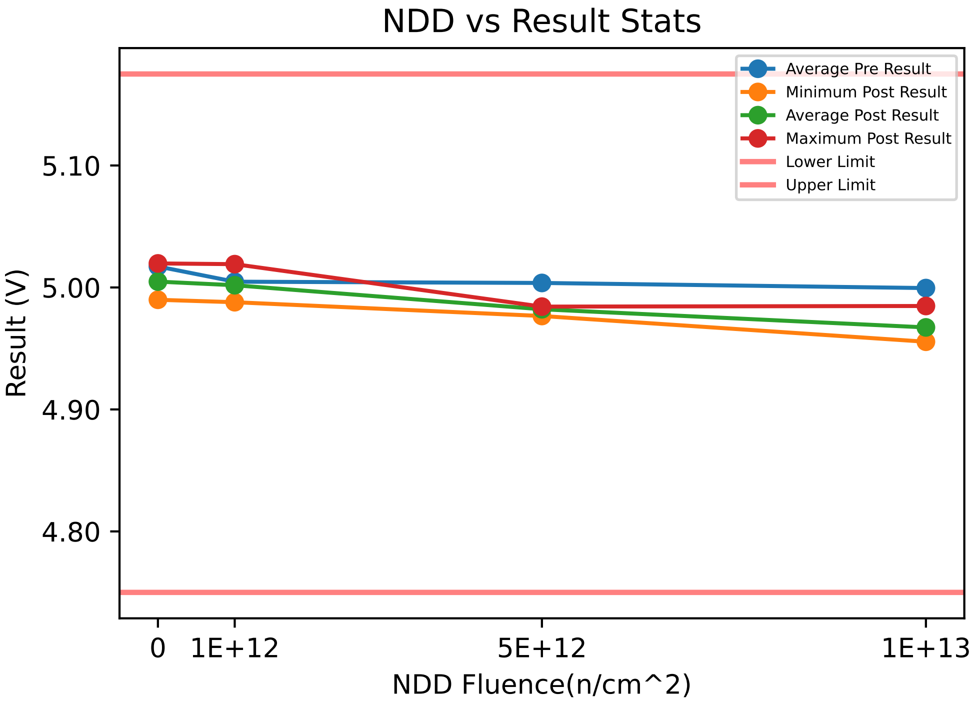
Test Results (Lower Limit = 6.65, Upper Limit = 7.35 (V))

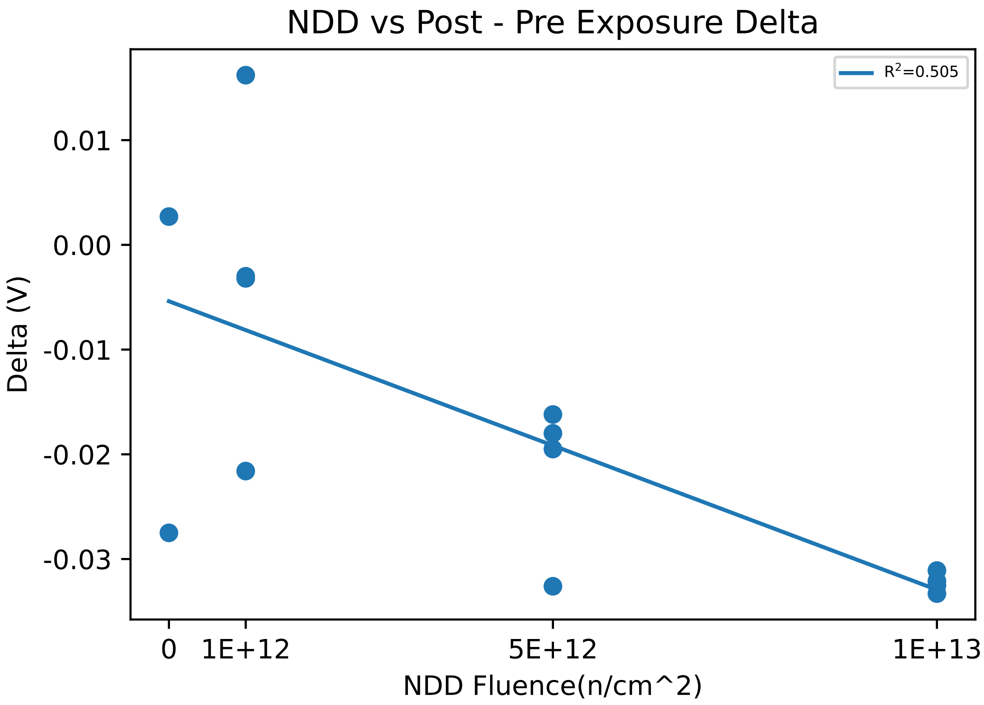
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	7.0016	7.0748	0.0732
2	0	Correlation	6.9946	7.0995	0.1049
30	1e+12	NDD unbiased	7.0298	7.0346	0.0048
31	1e+12	NDD unbiased	7.0388	7.0254	-0.0134
32	1e+12	NDD unbiased	6.9931	6.9884	-0.0047
33	1e+12	NDD unbiased	7.0103	7.0061	-0.0042
44	5e+12	NDD unbiased	7.0489	7.0236	-0.0253
45	5e+12	NDD unbiased	7.039	7.0092	-0.0298
46	5e+12	NDD unbiased	7.092	7.0654	-0.0266
47	5e+12	NDD unbiased	7.0371	7.0091	-0.028
50	1e+13	NDD unbiased	6.9567	6.915	-0.0417
51	1e+13	NDD unbiased	6.9585	6.9144	-0.0441
52	1e+13	NDD unbiased	6.9585	6.9156	-0.0429
53	1e+13	NDD unbiased	7.0077	6.9617	-0.046

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	6.9946	6.9981	7.0016	0.0049497	7.0748	7.0871	7.0995	0.017466	0.0732	0.08905	0.1049	0.022415
1e+12	6.9931	7.018	7.0388	0.020422	6.9884	7.0136	7.0346	0.020587	-0.0134	-0.004375	0.0048	0.0074334
5e+12	7.0371	7.0542	7.092	0.025693	7.0091	7.0268	7.0654	0.026604	-0.0298	-0.027425	-0.0253	0.0019294
1e+13	6.9567	6.9703	7.0077	0.024914	6.9144	6.9267	6.9617	0.023355	-0.046	-0.043675	-0.0417	0.0018337

Device Test: 62.4 V_BP5L(_V_BP5L PWM 1MHz VIN_14V)





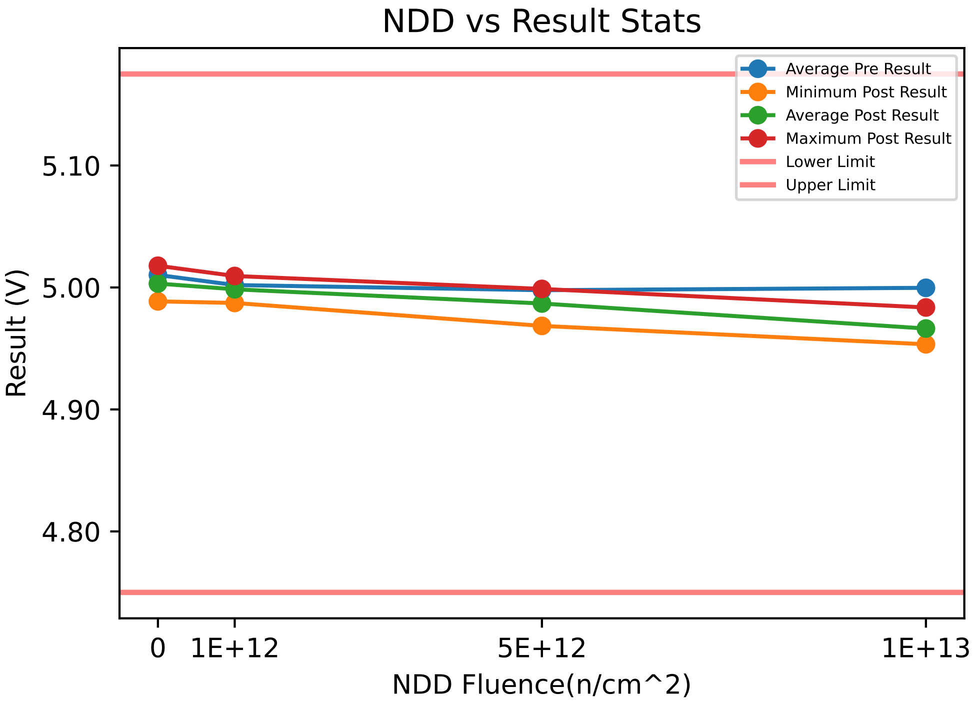
Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

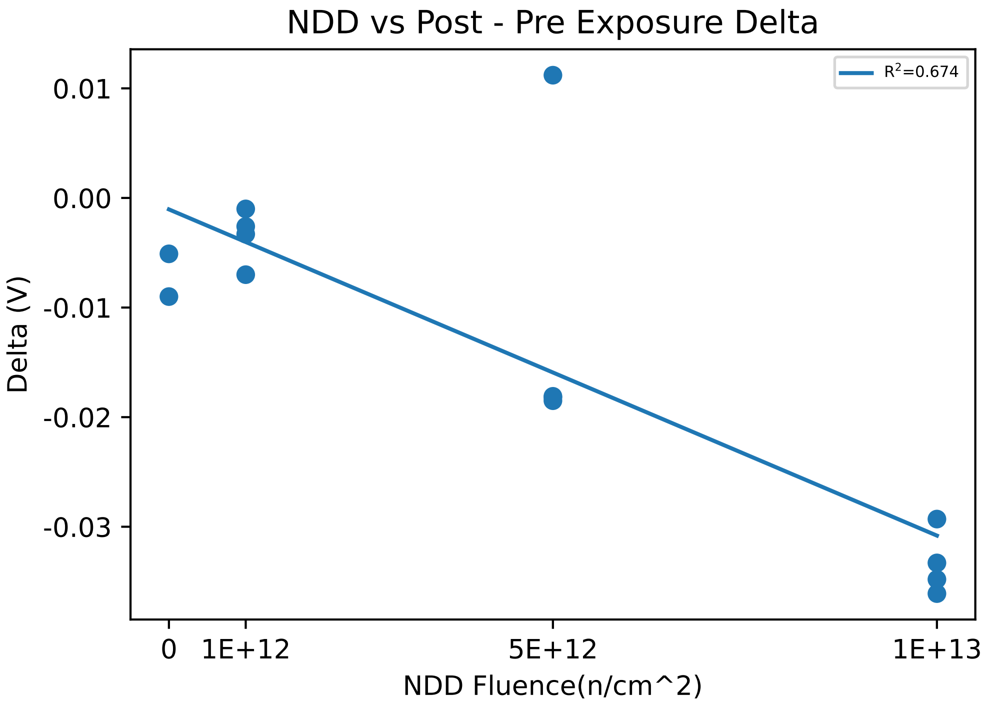
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	5.0174	4.9899	-0.0275
2	0	Correlation	5.017	5.0197	0.0027
30	1e+12	NDD unbiased	5.0222	5.0006	-0.0216
31	1e+12	NDD unbiased	5.0029	5.0191	0.0162
32	1e+12	NDD unbiased	5.0027	4.9997	-0.003
33	1e+12	NDD unbiased	4.9911	4.9879	-0.0032
44	5e+12	NDD unbiased	4.9928	4.9766	-0.0162
45	5e+12	NDD unbiased	5.0169	4.9843	-0.0326
46	5e+12	NDD unbiased	5.0015	4.9835	-0.018
47	5e+12	NDD unbiased	5.0036	4.9841	-0.0195
50	1e+13	NDD unbiased	4.9876	4.9555	-0.0321
51	1e+13	NDD unbiased	4.9997	4.9672	-0.0325
52	1e+13	NDD unbiased	5.0159	4.9848	-0.0311
53	1e+13	NDD unbiased	4.9948	4.9615	-0.0333

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.017	5.0172	5.0174	0.00028284	4.9899	5.0048	5.0197	0.021072	-0.0275	-0.0124	0.0027	0.021355
1e+12	4.9911	5.0047	5.0222	0.01289	4.9879	5.0018	5.0191	0.012889	-0.0216	-0.0029	0.0162	0.015434
5e+12	4.9928	5.0037	5.0169	0.0099649	4.9766	4.9821	4.9843	0.003699	-0.0326	-0.021575	-0.0162	0.0074728
1e+13	4.9876	4.9995	5.0159	0.01201	4.9555	4.9672	4.9848	0.012638	-0.0333	-0.03225	-0.0311	0.00091469

Device Test: 62.5 V_BP5H(_V_BP5H PWM 1MHz VIN_14V)





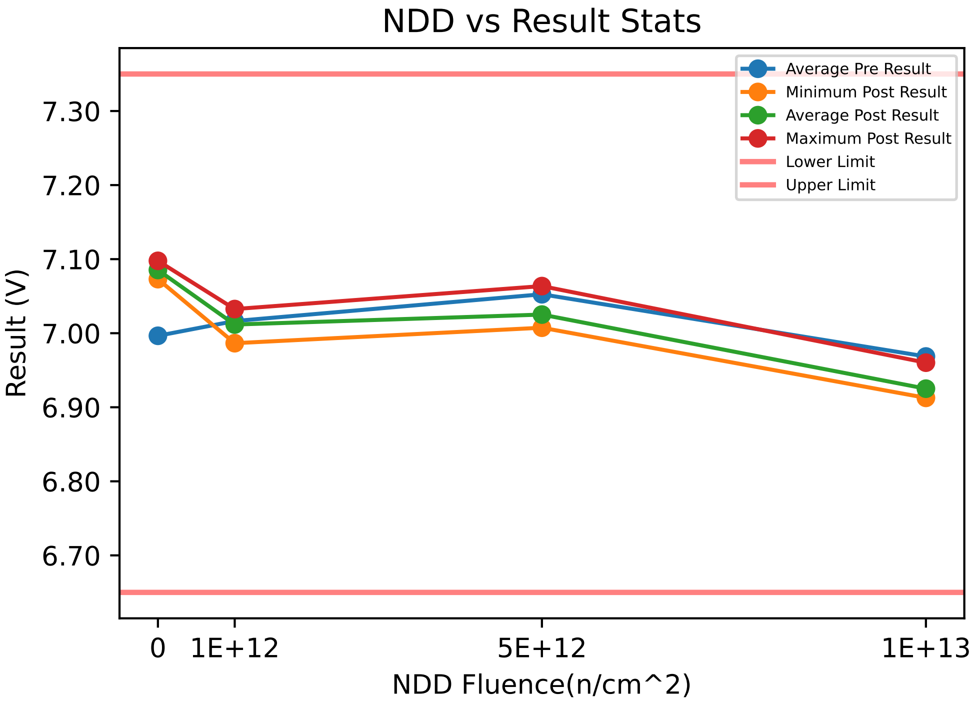
Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

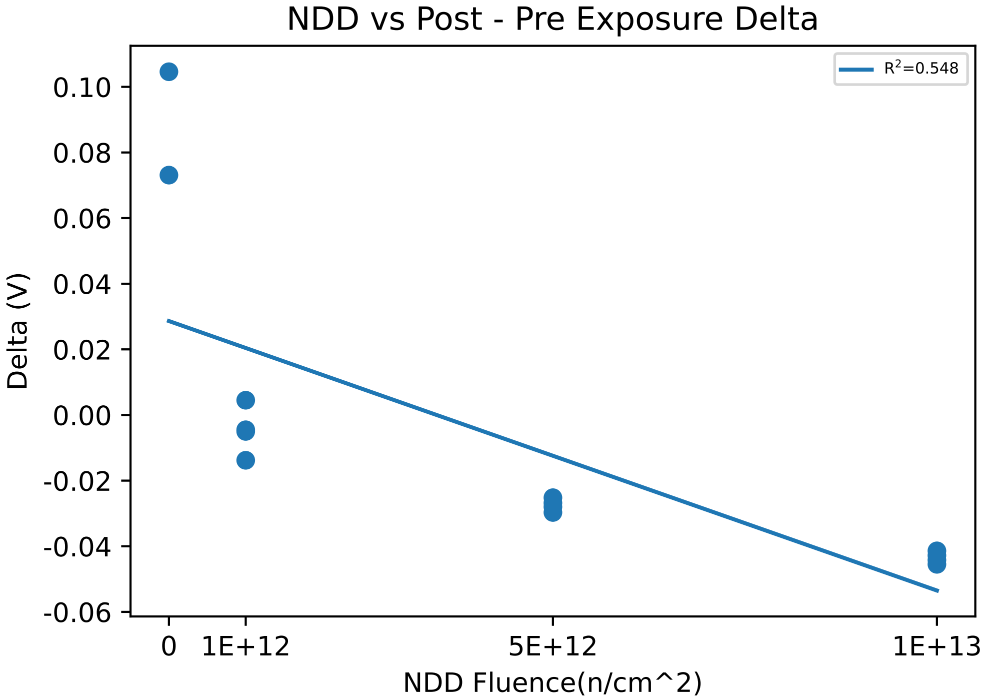
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	4.9976	4.9886	-0.009
2	0	Correlation	5.0229	5.0178	-0.0051
30	1e+12	NDD unbiased	4.9909	4.9899	-0.001
31	1e+12	NDD unbiased	4.9943	4.9873	-0.007
32	1e+12	NDD unbiased	5.0127	5.0094	-0.0033
33	1e+12	NDD unbiased	5.01	5.0074	-0.0026
44	5e+12	NDD unbiased	4.9998	4.9817	-0.0181
45	5e+12	NDD unbiased	4.9876	4.9988	0.0112
46	5e+12	NDD unbiased	4.987	4.9685	-0.0185
47	5e+12	NDD unbiased	5.0166	4.9984	-0.0182
50	1e+13	NDD unbiased	5.0169	4.9836	-0.0333
51	1e+13	NDD unbiased	4.9895	4.9534	-0.0361
52	1e+13	NDD unbiased	5.0009	4.9716	-0.0293
53	1e+13	NDD unbiased	4.9915	4.9567	-0.0348

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.9976	5.0103	5.0229	0.01789	4.9886	5.0032	5.0178	0.020648	-0.009	-0.00705	-0.0051	0.0027577
1e+12	4.9909	5.002	5.0127	0.010969	4.9873	4.9985	5.0094	0.01151	-0.007	-0.003475	-0.001	0.0025395
5e+12	4.987	4.9977	5.0166	0.013882	4.9685	4.9869	4.9988	0.0146	-0.0185	-0.0109	0.0112	0.014734
1e+13	4.9895	4.9997	5.0169	0.012497	4.9534	4.9663	4.9836	0.013976	-0.0361	-0.033375	-0.0293	0.0029477

Device Test: 62.6 V_BP7L(_V_BP7L PWM 2MHz VIN_14V)





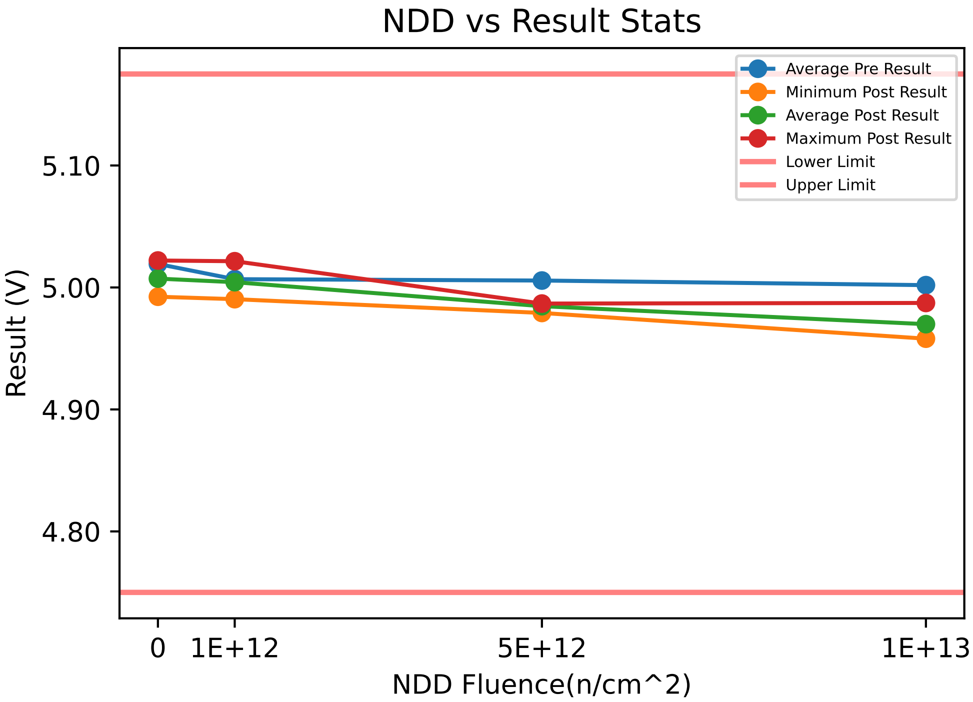
Test Results (Lower Limit = 6.65, Upper Limit = 7.35 (V))

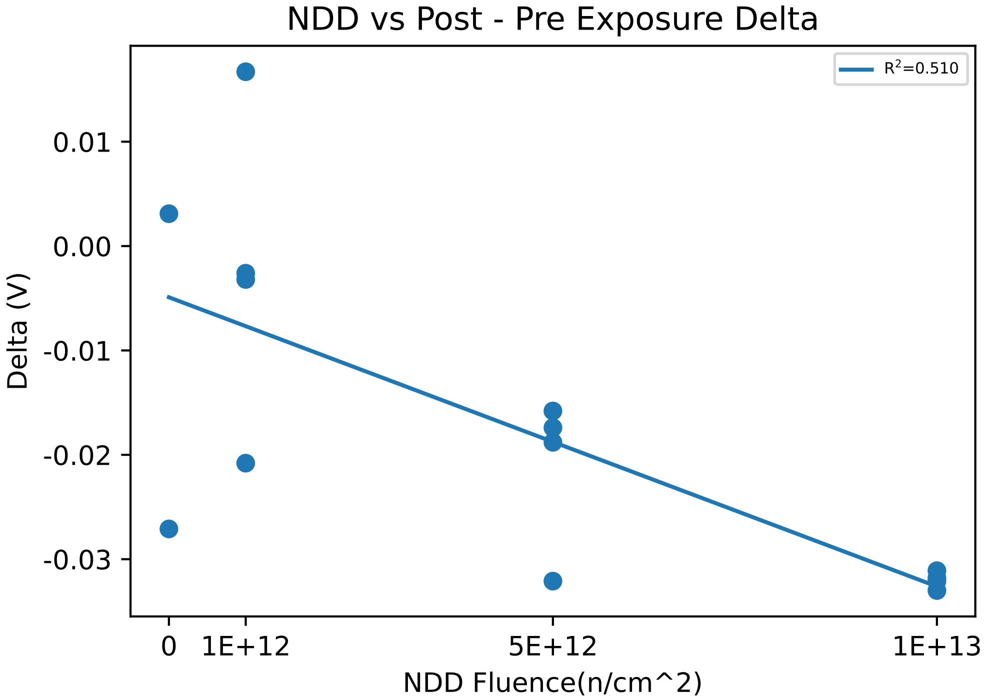
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	6.9999	7.073	0.0731
2	0	Correlation	6.9931	7.0977	0.1046
30	1e+12	NDD unbiased	7.0281	7.0326	0.0045
31	1e+12	NDD unbiased	7.0374	7.0236	-0.0138
32	1e+12	NDD unbiased	6.9915	6.9865	-0.005
33	1e+12	NDD unbiased	7.0086	7.0041	-0.0045
44	5e+12	NDD unbiased	7.0472	7.022	-0.0252
45	5e+12	NDD unbiased	7.0373	7.0076	-0.0297
46	5e+12	NDD unbiased	7.0904	7.0636	-0.0268
47	5e+12	NDD unbiased	7.0354	7.0074	-0.028
50	1e+13	NDD unbiased	6.9548	6.9134	-0.0414
51	1e+13	NDD unbiased	6.9569	6.9127	-0.0442
52	1e+13	NDD unbiased	6.9568	6.914	-0.0428
53	1e+13	NDD unbiased	7.0057	6.9602	-0.0455

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	6.9931	6.9965	6.9999	0.0048083	7.073	7.0854	7.0977	0.017466	0.0731	0.08885	0.1046	0.022274
1e+12	6.9915	7.0164	7.0374	0.020484	6.9865	7.0117	7.0326	0.020585	-0.0138	-0.0047	0.0045	0.007474
5e+12	7.0354	7.0526	7.0904	0.025742	7.0074	7.0252	7.0636	0.026529	-0.0297	-0.027425	-0.0252	0.0019015
1e+13	6.9548	6.9686	7.0057	0.024786	6.9127	6.9251	6.9602	0.023423	-0.0455	-0.043475	-0.0414	0.0017689

Device Test: 62.7 V_BP5L(_V_BP5L PWM 2MHz VIN_14V)


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

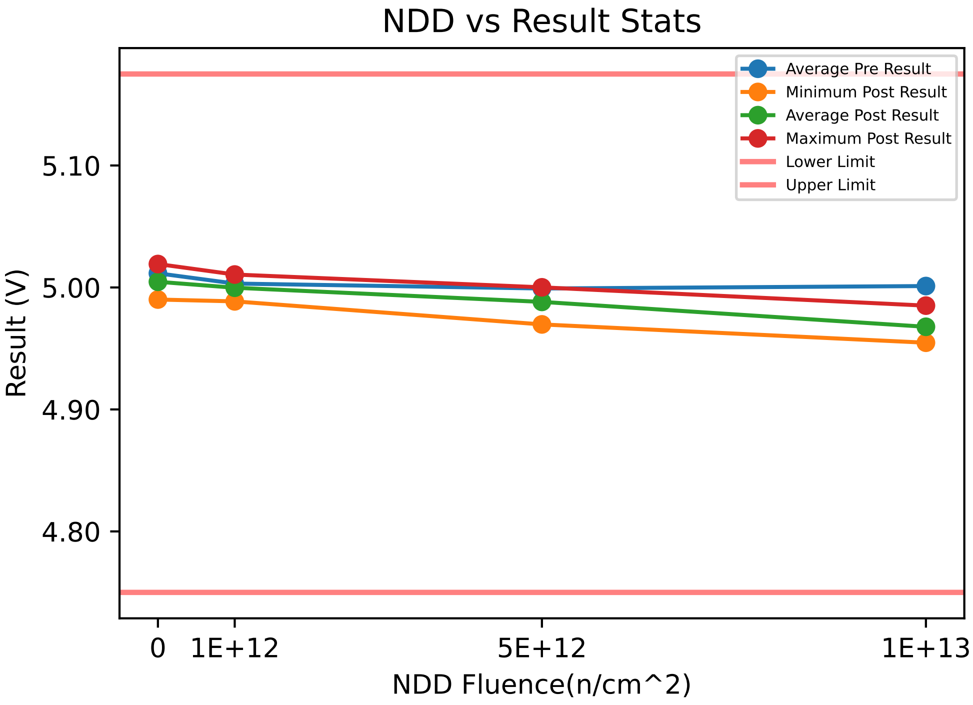
Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

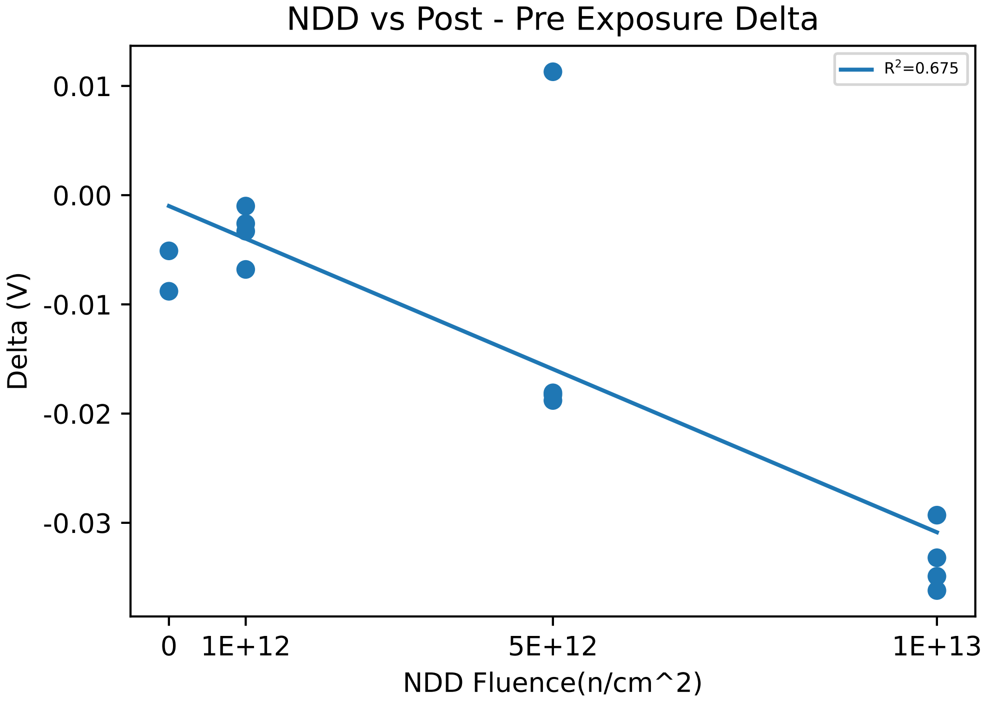
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	5.0195	4.9924	-0.0271
2	0	Correlation	5.019	5.0221	0.0031
30	1e+12	NDD unbiased	5.0241	5.0033	-0.0208
31	1e+12	NDD unbiased	5.0048	5.0215	0.0167
32	1e+12	NDD unbiased	5.0047	5.0021	-0.0026
33	1e+12	NDD unbiased	4.9936	4.9904	-0.0032
44	5e+12	NDD unbiased	4.9949	4.9791	-0.0158
45	5e+12	NDD unbiased	5.0189	4.9868	-0.0321
46	5e+12	NDD unbiased	5.0035	4.9861	-0.0174
47	5e+12	NDD unbiased	5.0054	4.9866	-0.0188
50	1e+13	NDD unbiased	4.9901	4.958	-0.0321
51	1e+13	NDD unbiased	5.0019	4.9701	-0.0318
52	1e+13	NDD unbiased	5.0184	4.9873	-0.0311
53	1e+13	NDD unbiased	4.9972	4.9642	-0.033

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.019	5.0192	5.0195	0.00035355	4.9924	5.0072	5.0221	0.021001	-0.0271	-0.012	0.0031	0.021355
1e+12	4.9936	5.0068	5.0241	0.012675	4.9904	5.0043	5.0215	0.012844	-0.0208	-0.002475	0.0167	0.015319
5e+12	4.9949	5.0057	5.0189	0.0099299	4.9791	4.9847	4.9868	0.0037117	-0.0321	-0.021025	-0.0158	0.0074844
1e+13	4.9901	5.0019	5.0184	0.012022	4.958	4.9699	4.9873	0.012608	-0.033	-0.032	-0.0311	0.0007874

Device Test: 62.8 V_BP5H(_V_BP5H PWM 2MHz VIN_14V)





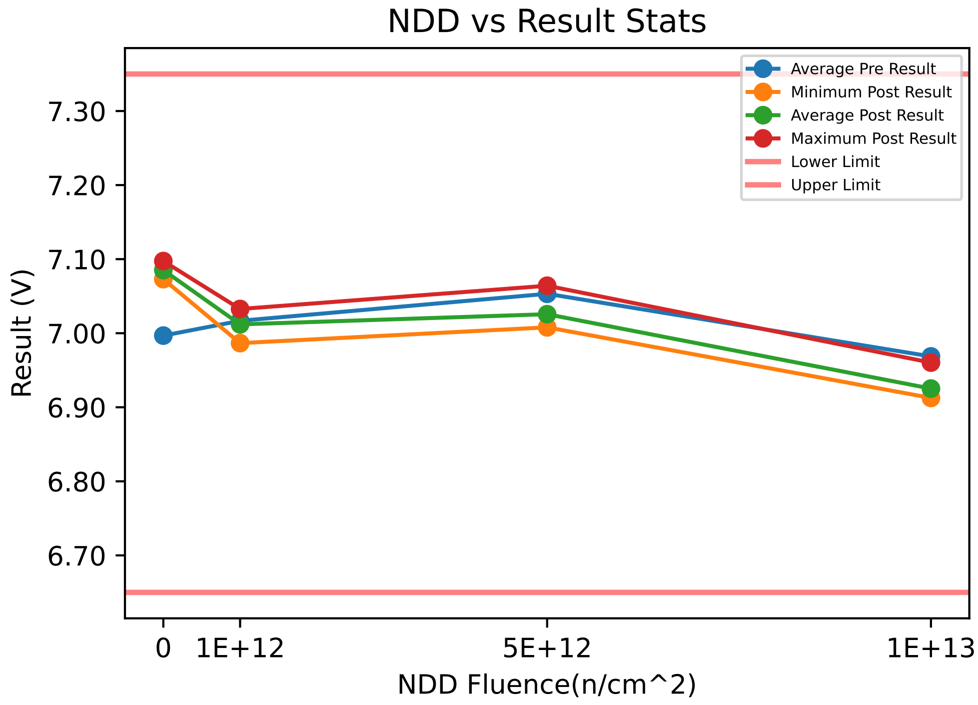
Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

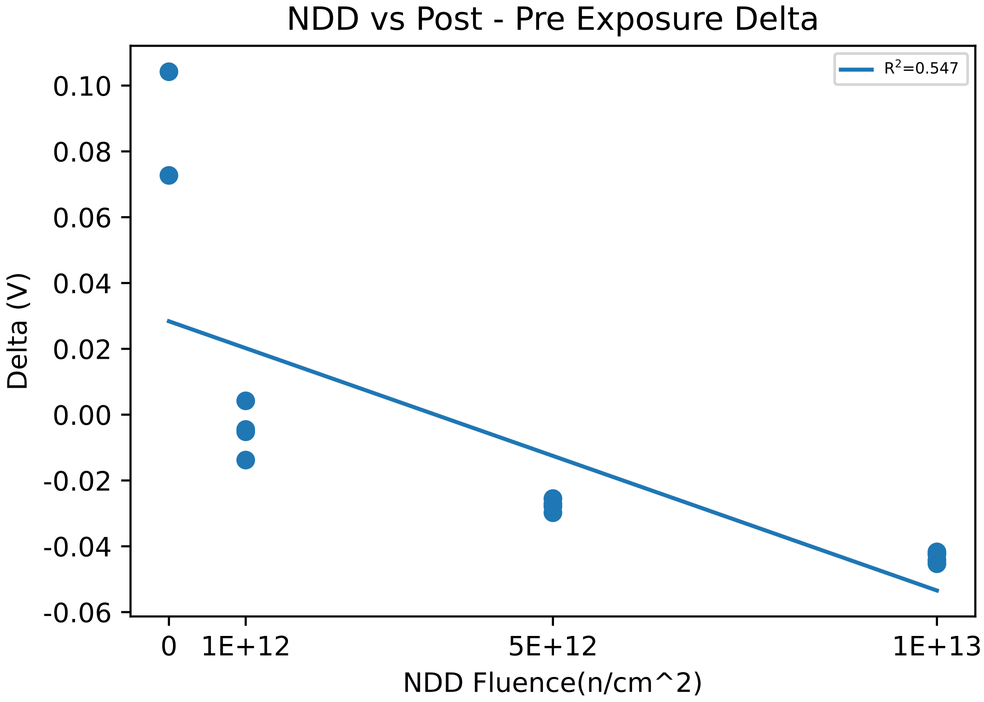
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	4.9989	4.9901	-0.0088
2	0	Correlation	5.0243	5.0192	-0.0051
30	1e+12	NDD unbiased	4.9921	4.9911	-0.001
31	1e+12	NDD unbiased	4.9954	4.9886	-0.0068
32	1e+12	NDD unbiased	5.0139	5.0106	-0.0033
33	1e+12	NDD unbiased	5.0114	5.0088	-0.0026
44	5e+12	NDD unbiased	5.0013	4.9832	-0.0181
45	5e+12	NDD unbiased	4.9888	5.0001	0.0113
46	5e+12	NDD unbiased	4.9885	4.9697	-0.0188
47	5e+12	NDD unbiased	5.018	4.9997	-0.0183
50	1e+13	NDD unbiased	5.0183	4.9851	-0.0332
51	1e+13	NDD unbiased	4.9909	4.9547	-0.0362
52	1e+13	NDD unbiased	5.0024	4.9731	-0.0293
53	1e+13	NDD unbiased	4.993	4.9581	-0.0349

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.9989	5.0116	5.0243	0.017961	4.9901	5.0046	5.0192	0.020577	-0.0088	-0.00695	-0.0051	0.0026163
1e+12	4.9921	5.0032	5.0139	0.011042	4.9886	4.9998	5.0106	0.011529	-0.0068	-0.003425	-0.001	0.0024473
5e+12	4.9885	4.9992	5.018	0.01391	4.9697	4.9882	5.0001	0.014619	-0.0188	-0.010975	0.0113	0.014853
1e+13	4.9909	5.0011	5.0183	0.012479	4.9547	4.9677	4.9851	0.01406	-0.0362	-0.0334	-0.0293	0.0029967

Device Test: 62.9 V_BP7L(_V_BP7L PWM 5MHz VIN_14V)


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

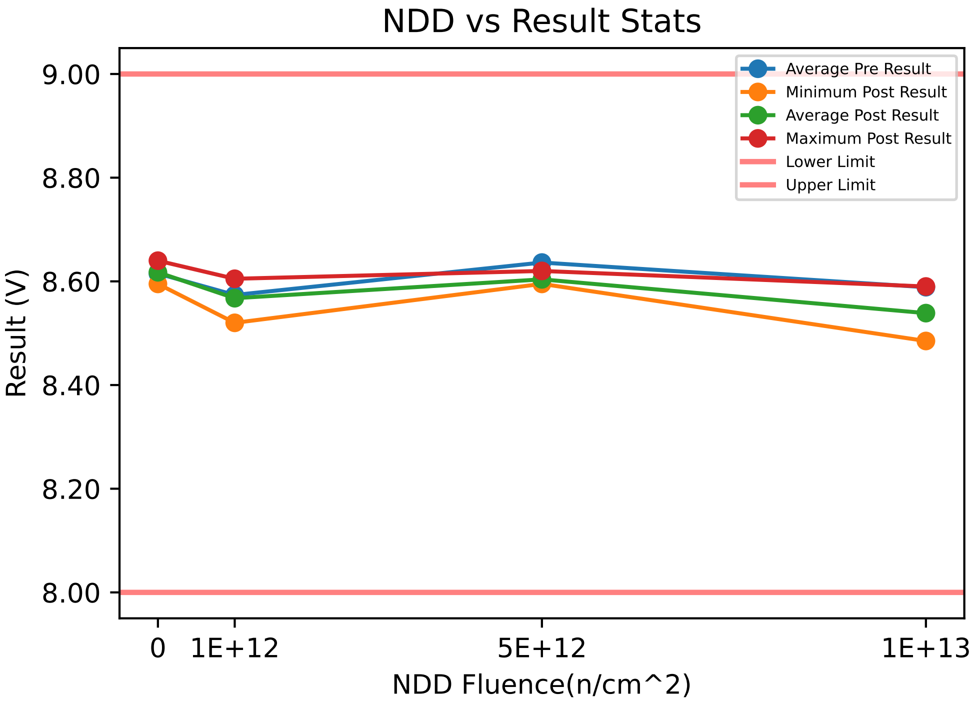
Test Results (Lower Limit = 6.65, Upper Limit = 7.35 (V))

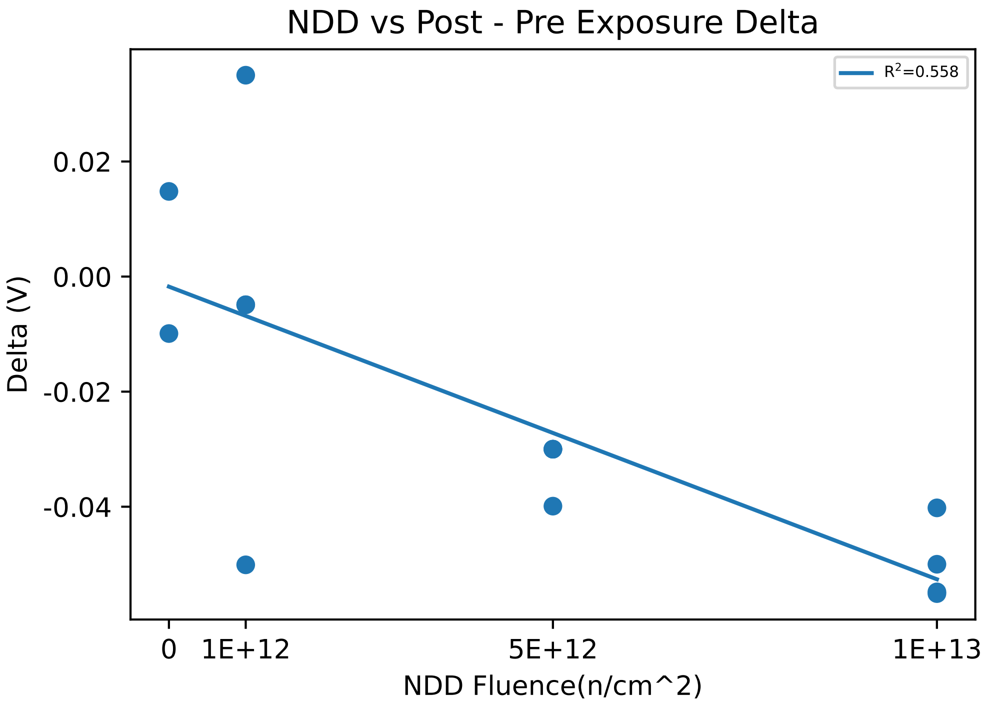
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	7.0003	7.073	0.0727
2	0	Correlation	6.9932	7.0974	0.1042
30	1e+12	NDD unbiased	7.0285	7.0327	0.0042
31	1e+12	NDD unbiased	7.0376	7.0238	-0.0138
32	1e+12	NDD unbiased	6.9918	6.9866	-0.0052
33	1e+12	NDD unbiased	7.0091	7.0046	-0.0045
44	5e+12	NDD unbiased	7.048	7.0225	-0.0255
45	5e+12	NDD unbiased	7.0379	7.0081	-0.0298
46	5e+12	NDD unbiased	7.0911	7.0641	-0.027
47	5e+12	NDD unbiased	7.0358	7.0079	-0.0279
50	1e+13	NDD unbiased	6.9552	6.9135	-0.0417
51	1e+13	NDD unbiased	6.9568	6.9126	-0.0442
52	1e+13	NDD unbiased	6.957	6.9145	-0.0425
53	1e+13	NDD unbiased	7.0056	6.9603	-0.0453

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	6.9932	6.9968	7.0003	0.0050205	7.073	7.0852	7.0974	0.017253	0.0727	0.08845	0.1042	0.022274
1e+12	6.9918	7.0168	7.0376	0.020443	6.9866	7.0119	7.0327	0.020556	-0.0138	-0.004825	0.0042	0.0073541
5e+12	7.0358	7.0532	7.0911	0.025822	7.0079	7.0256	7.0641	0.026529	-0.0298	-0.02755	-0.0255	0.0017972
1e+13	6.9552	6.9687	7.0056	0.024647	6.9126	6.9252	6.9603	0.023396	-0.0453	-0.043425	-0.0417	0.0016276

Device Test: 70.0 V_IN_TH_RISE(_UVLO VIN Rise Thresh)


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

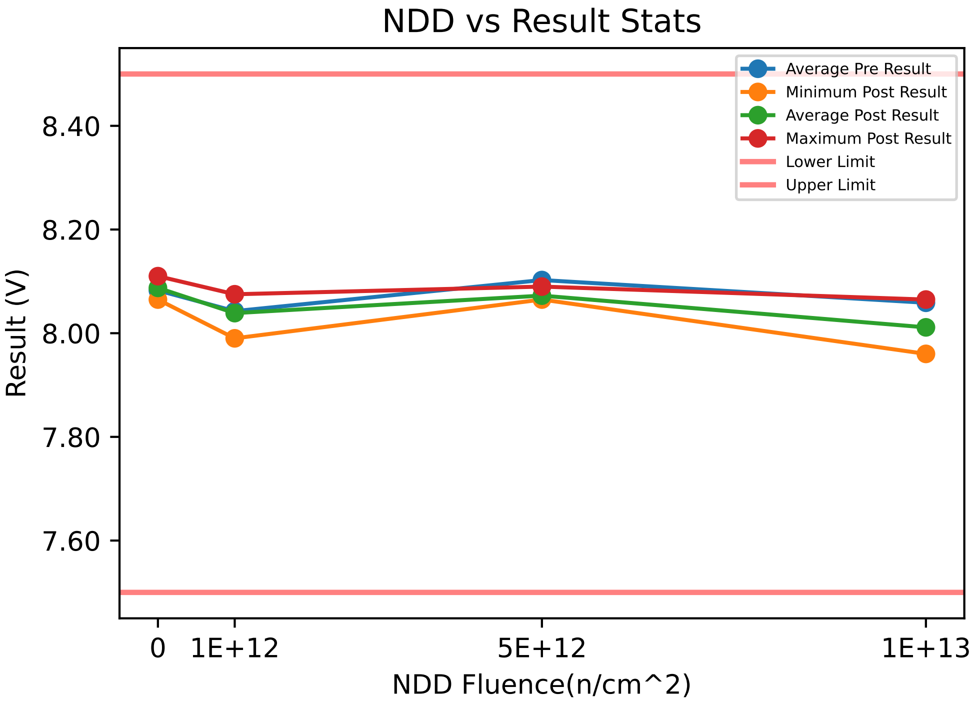
Test Results (Lower Limit = 8.0, Upper Limit = 9.0 (V))

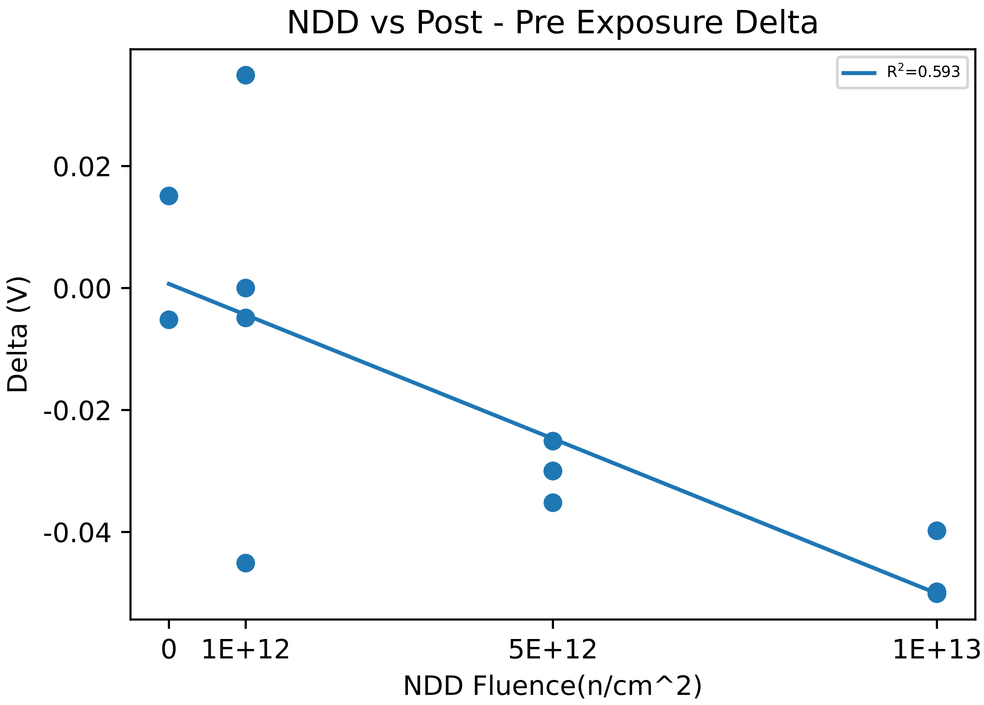
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	8.605	8.5951	-0.0099
2	0	Correlation	8.6251	8.6399	0.0148
30	1e+12	NDD unbiased	8.6	8.5499	-0.0501
31	1e+12	NDD unbiased	8.5601	8.5951	0.035
32	1e+12	NDD unbiased	8.6099	8.605	-0.0049
33	1e+12	NDD unbiased	8.5249	8.52	-0.0049
44	5e+12	NDD unbiased	8.6501	8.6201	-0.03
45	5e+12	NDD unbiased	8.635	8.5951	-0.0399
46	5e+12	NDD unbiased	8.635	8.605	-0.03
47	5e+12	NDD unbiased	8.6251	8.5951	-0.03
50	1e+13	NDD unbiased	8.5901	8.5499	-0.0402
51	1e+13	NDD unbiased	8.5799	8.5299	-0.05
52	1e+13	NDD unbiased	8.5401	8.485	-0.0551
53	1e+13	NDD unbiased	8.6449	8.5901	-0.0548

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	8.605	8.6151	8.6251	0.014213	8.5951	8.6175	8.6399	0.031678	-0.0099	0.00245	0.0148	0.017466
1e+12	8.5249	8.5737	8.6099	0.039024	8.52	8.5675	8.605	0.039724	-0.0501	-0.006225	0.035	0.034776
5e+12	8.6251	8.6363	8.6501	0.010316	8.5951	8.6038	8.6201	0.011811	-0.0399	-0.032475	-0.03	0.00495
1e+13	8.5401	8.5888	8.6449	0.043204	8.485	8.5387	8.5901	0.043698	-0.0551	-0.050025	-0.0402	0.0069543

Device Test: 70.1 V_IN_TH_FALL(_UVLO VIN Fall Thresh)


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

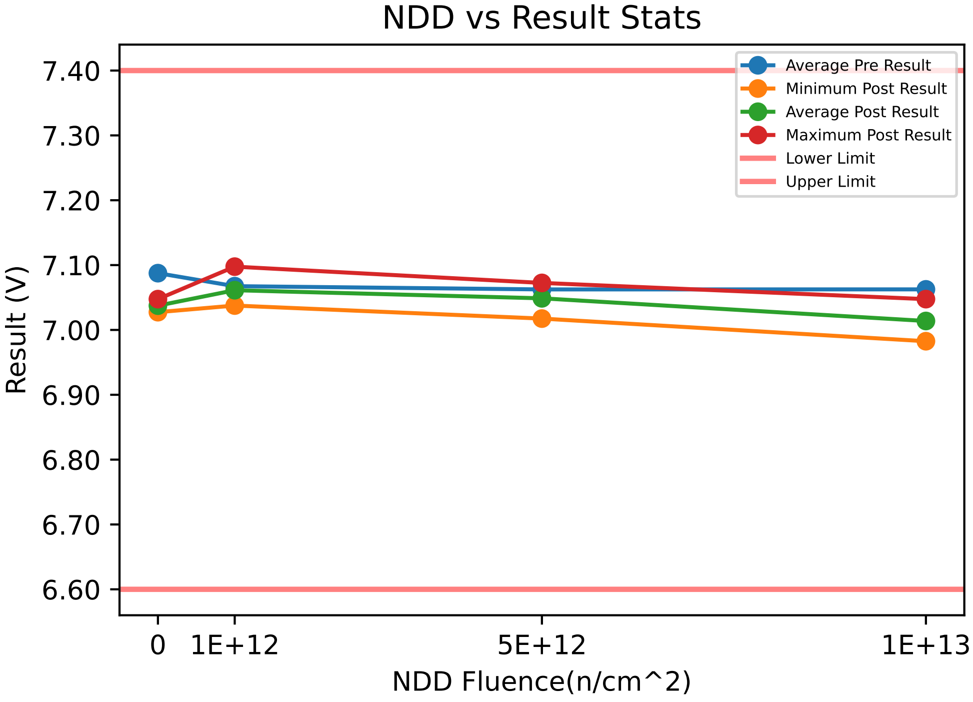
Test Results (Lower Limit = 7.5, Upper Limit = 8.5 (V))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	8.0701	8.0649	-0.0052
2	0	Correlation	8.0949	8.11	0.0151
30	1e+12	NDD unbiased	8.0701	8.025	-0.0451
31	1e+12	NDD unbiased	8.03	8.0649	0.0349
32	1e+12	NDD unbiased	8.0751	8.0751	0
33	1e+12	NDD unbiased	7.995	7.9901	-0.0049
44	5e+12	NDD unbiased	8.115	8.0899	-0.0251
45	5e+12	NDD unbiased	8.1001	8.0649	-0.0352
46	5e+12	NDD unbiased	8.1001	8.0701	-0.03
47	5e+12	NDD unbiased	8.0949	8.0649	-0.03
50	1e+13	NDD unbiased	8.0599	8.0201	-0.0398
51	1e+13	NDD unbiased	8.0501	8	-0.0501
52	1e+13	NDD unbiased	8.0099	7.9601	-0.0498
53	1e+13	NDD unbiased	8.115	8.0649	-0.0501

Test Statistics (V)

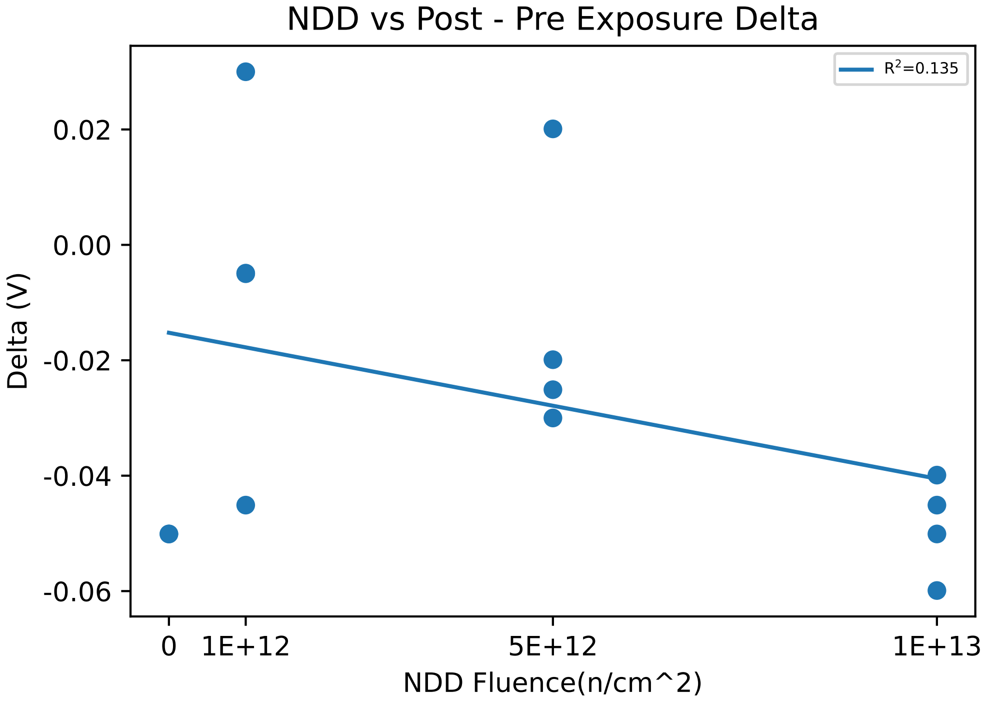
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	8.0701	8.0825	8.0949	0.017536	8.0649	8.0875	8.11	0.031891	-0.0052	0.00495	0.0151	0.014354
1e+12	7.995	8.0426	8.0751	0.037581	7.9901	8.0388	8.0751	0.038992	-0.0451	-0.003775	0.0349	0.032757
5e+12	8.0949	8.1025	8.115	0.0086704	8.0649	8.0724	8.0899	0.011889	-0.0352	-0.030075	-0.0251	0.0041242
1e+13	8.0099	8.0587	8.115	0.043307	7.9601	8.0113	8.0649	0.043587	-0.0501	-0.04745	-0.0398	0.005102

Device Test: 75.0 V_BOOT_TH_RISE(_UVLO BOOT Rise Thresh)



Test Results (Lower Limit = 6.6, Upper Limit = 7.4 (V))

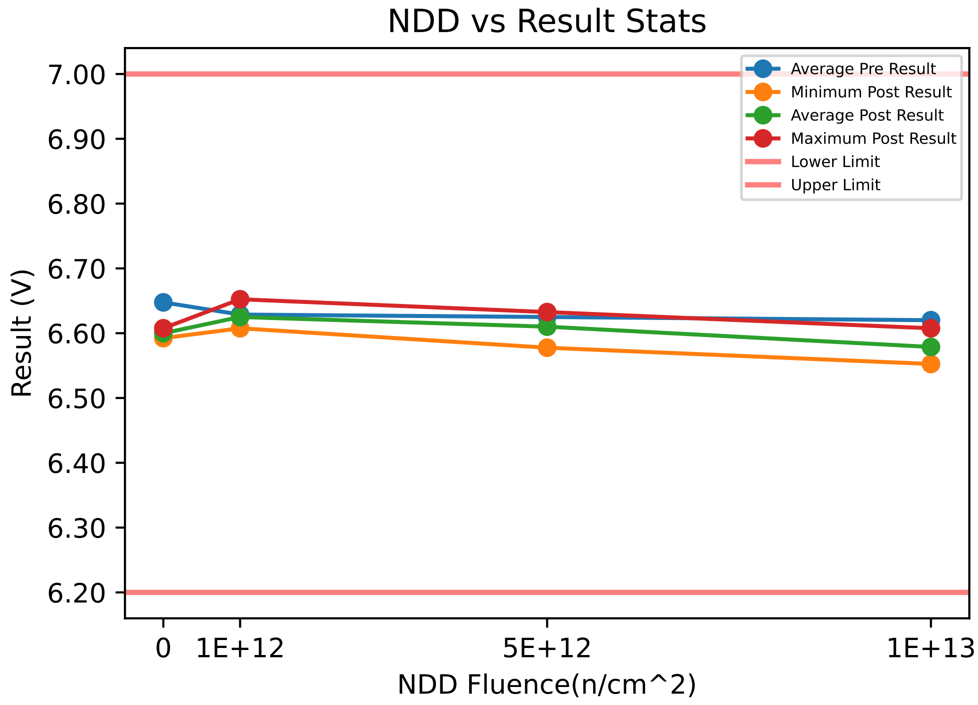
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	7.0976	7.0475	-0.0501
2	0	Correlation	7.0775	7.0274	-0.0501
30	1e+12	NDD unbiased	7.1025	7.0574	-0.0451
31	1e+12	NDD unbiased	7.0676	7.0976	0.03
32	1e+12	NDD unbiased	7.0574	7.0524	-0.005
33	1e+12	NDD unbiased	7.0425	7.0376	-0.0049
44	5e+12	NDD unbiased	7.0475	7.0175	-0.03
45	5e+12	NDD unbiased	7.0524	7.0725	0.0201
46	5e+12	NDD unbiased	7.0524	7.0325	-0.0199
47	5e+12	NDD unbiased	7.0976	7.0725	-0.0251
50	1e+13	NDD unbiased	7.0775	7.0376	-0.0399
51	1e+13	NDD unbiased	7.0376	6.9875	-0.0501
52	1e+13	NDD unbiased	7.0926	7.0475	-0.0451
53	1e+13	NDD unbiased	7.0425	6.9826	-0.0599

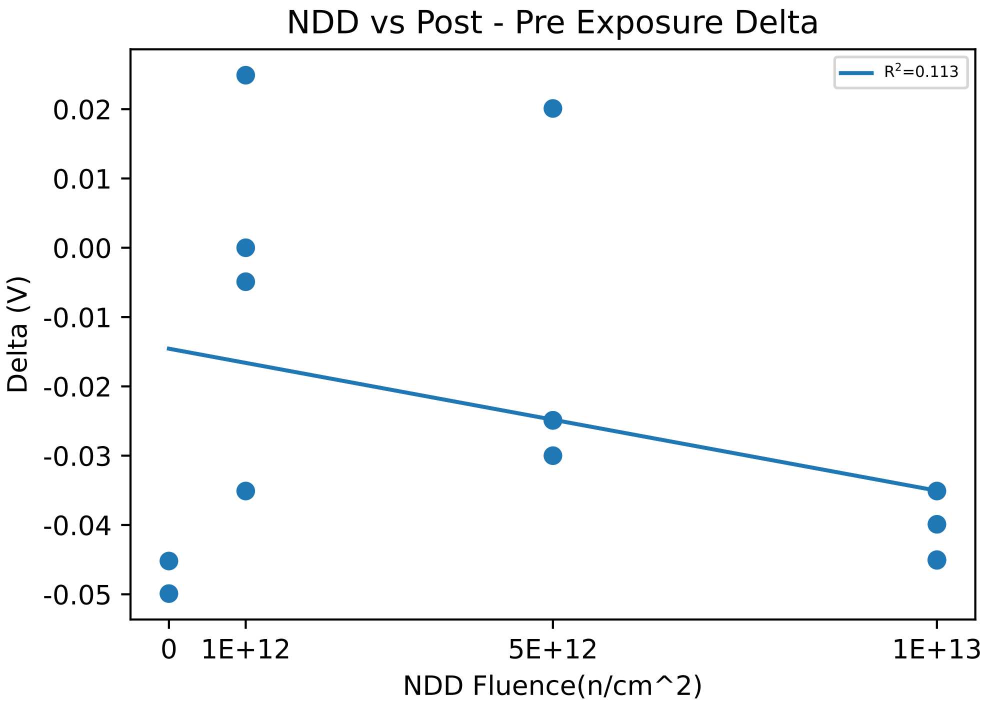


Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	7.0775	7.0876	7.0976	0.014213	7.0274	7.0374	7.0475	0.014213	-0.0501	-0.0501	-0.0501	0
1e+12	7.0425	7.0675	7.1025	0.025508	7.0376	7.0613	7.0976	0.02565	-0.0451	-0.00625	0.03	0.030696
5e+12	7.0475	7.0625	7.0976	0.02353	7.0175	7.0488	7.0725	0.0281	-0.03	-0.013725	0.0201	0.022924
1e+13	7.0376	7.0625	7.0926	0.026777	6.9826	7.0138	7.0475	0.033503	-0.0599	-0.04875	-0.0399	0.0085204

Device Test: 75.1 V_BOOT_TH_FALL(_UVLO BOOT Fall Thresh)


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

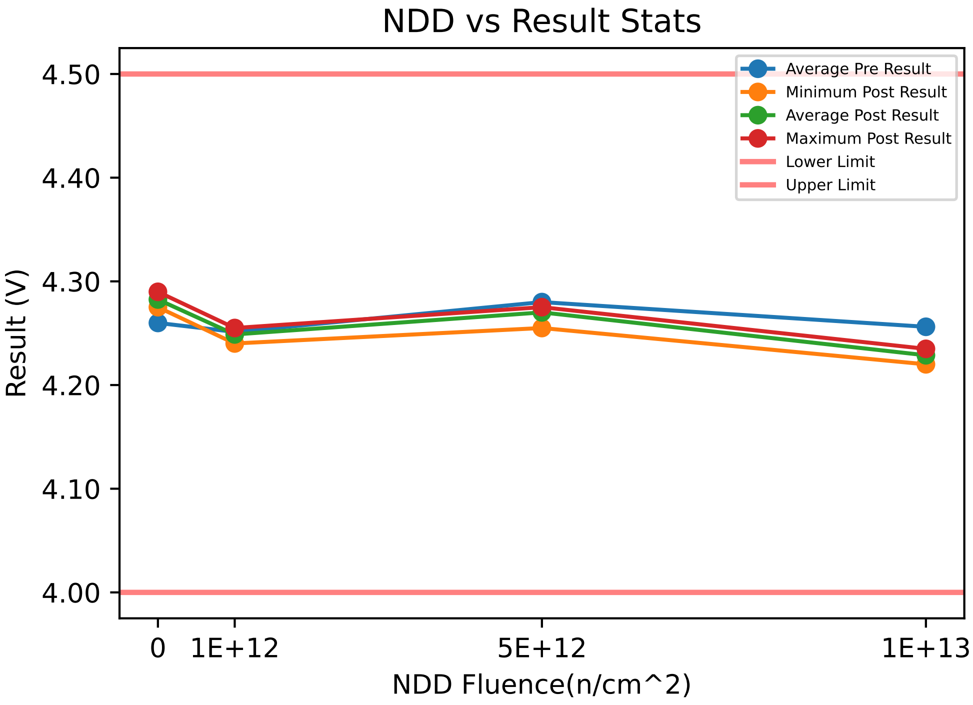
Test Results (Lower Limit = 6.2, Upper Limit = 7.0 (V))

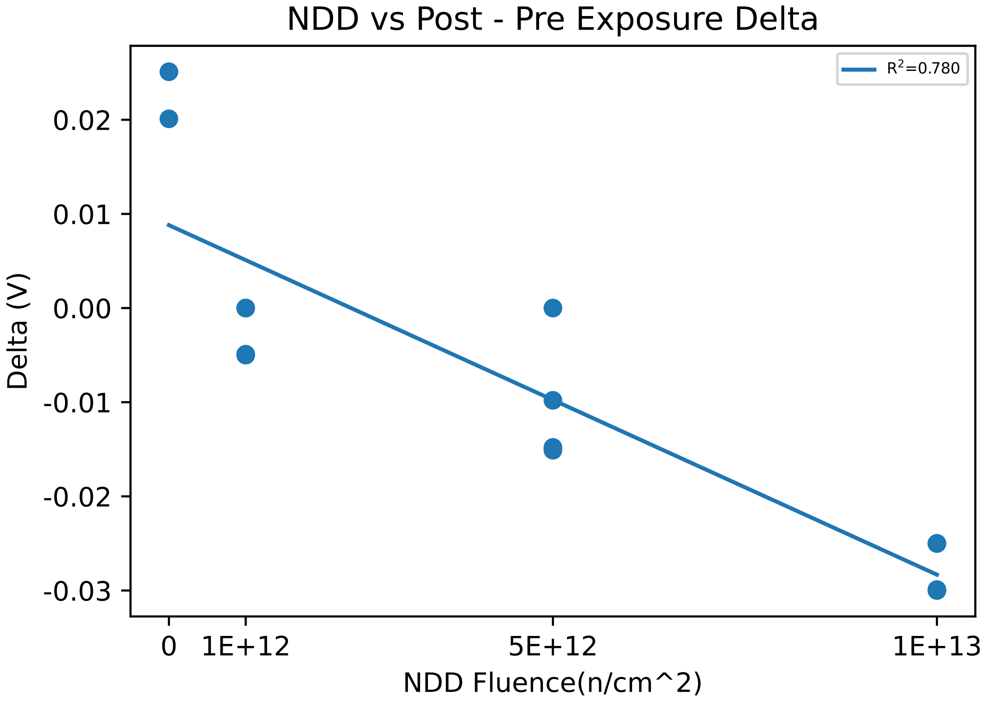
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	6.6575	6.6076	-0.0499
2	0	Correlation	6.6376	6.5924	-0.0452
30	1e+12	NDD unbiased	6.6575	6.6224	-0.0351
31	1e+12	NDD unbiased	6.6275	6.6524	0.0249
32	1e+12	NDD unbiased	6.6224	6.6175	-0.0049
33	1e+12	NDD unbiased	6.6076	6.6076	0
44	5e+12	NDD unbiased	6.6076	6.5776	-0.03
45	5e+12	NDD unbiased	6.6125	6.6326	0.0201
46	5e+12	NDD unbiased	6.6224	6.5975	-0.0249
47	5e+12	NDD unbiased	6.6575	6.6326	-0.0249
50	1e+13	NDD unbiased	6.6326	6.5975	-0.0351
51	1e+13	NDD unbiased	6.5975	6.5525	-0.045
52	1e+13	NDD unbiased	6.6475	6.6076	-0.0399
53	1e+13	NDD unbiased	6.6026	6.5575	-0.0451

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	6.6376	6.6475	6.6575	0.014071	6.5924	6.6	6.6076	0.010748	-0.0499	-0.04755	-0.0452	0.0033234
1e+12	6.6076	6.6288	6.6575	0.020943	6.6076	6.625	6.6524	0.019292	-0.0351	-0.003775	0.0249	0.024624
5e+12	6.6076	6.625	6.6575	0.022524	6.5776	6.6101	6.6326	0.027249	-0.03	-0.014925	0.0201	0.023473
1e+13	6.5975	6.62	6.6475	0.023972	6.5525	6.5788	6.6076	0.027836	-0.0451	-0.041275	-0.0351	0.0047794

Device Test: 80.1 V_BP5L_TH_RISE(_UVLO BP5L Rise Thresh VIN_10V)





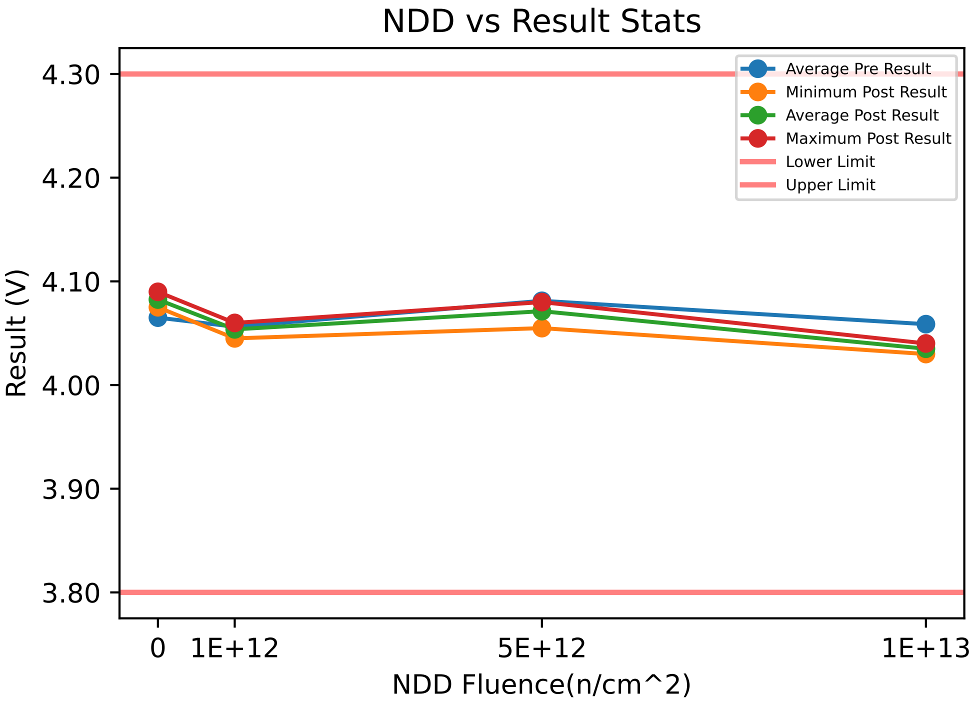
Test Results (Lower Limit = 4.0, Upper Limit = 4.5 (V))

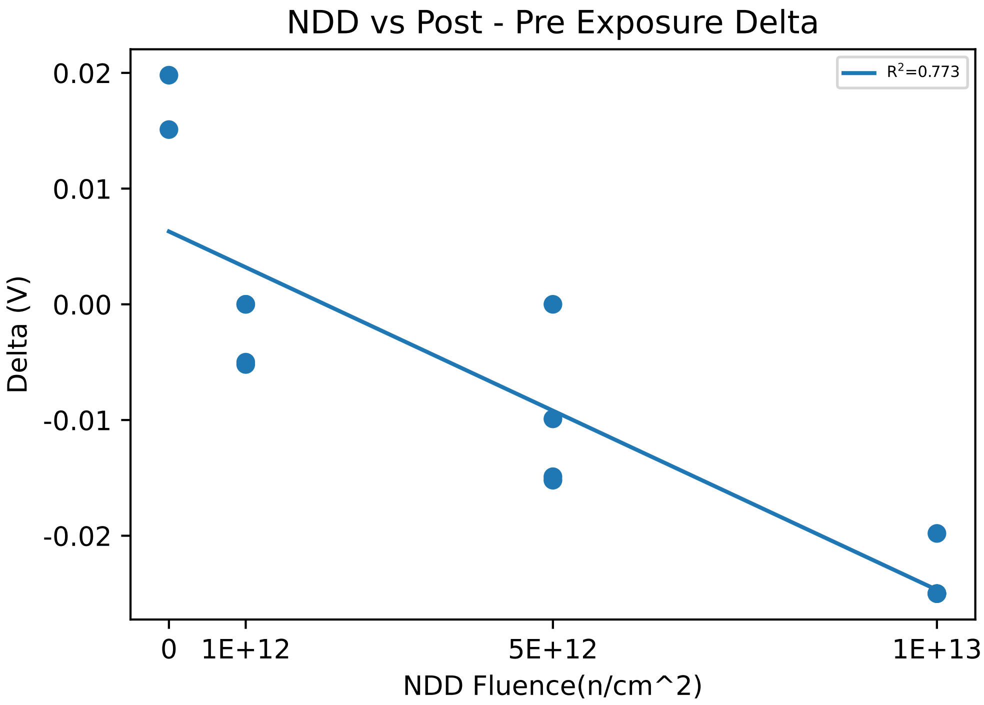
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	4.2648	4.2899	0.0251
2	0	Correlation	4.255	4.2751	0.0201
30	1e+12	NDD unbiased	4.2599	4.255	-0.0049
31	1e+12	NDD unbiased	4.255	4.255	0
32	1e+12	NDD unbiased	4.2451	4.2401	-0.005
33	1e+12	NDD unbiased	4.2451	4.2451	0
44	5e+12	NDD unbiased	4.2849	4.2751	-0.0098
45	5e+12	NDD unbiased	4.2751	4.2751	0
46	5e+12	NDD unbiased	4.2701	4.255	-0.0151
47	5e+12	NDD unbiased	4.2899	4.2751	-0.0148
50	1e+13	NDD unbiased	4.25	4.22	-0.03
51	1e+13	NDD unbiased	4.2599	4.2349	-0.025
52	1e+13	NDD unbiased	4.25	4.225	-0.025
53	1e+13	NDD unbiased	4.2648	4.2349	-0.0299

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.255	4.2599	4.2648	0.0069296	4.2751	4.2825	4.2899	0.010465	0.0201	0.0226	0.0251	0.0035355
1e+12	4.2451	4.2513	4.2599	0.0074056	4.2401	4.2488	4.255	0.0074445	-0.005	-0.002475	0	0.0028582
5e+12	4.2701	4.28	4.2899	0.0090192	4.255	4.2701	4.2751	0.01005	-0.0151	-0.009925	0	0.0070491
1e+13	4.25	4.2562	4.2648	0.0074056	4.22	4.2287	4.2349	0.0074445	-0.03	-0.027475	-0.025	0.0028582

Device Test: 80.2 V_BP5L_TH_FALL(_UVLO BP5L Fall Thresh VIN_10V)





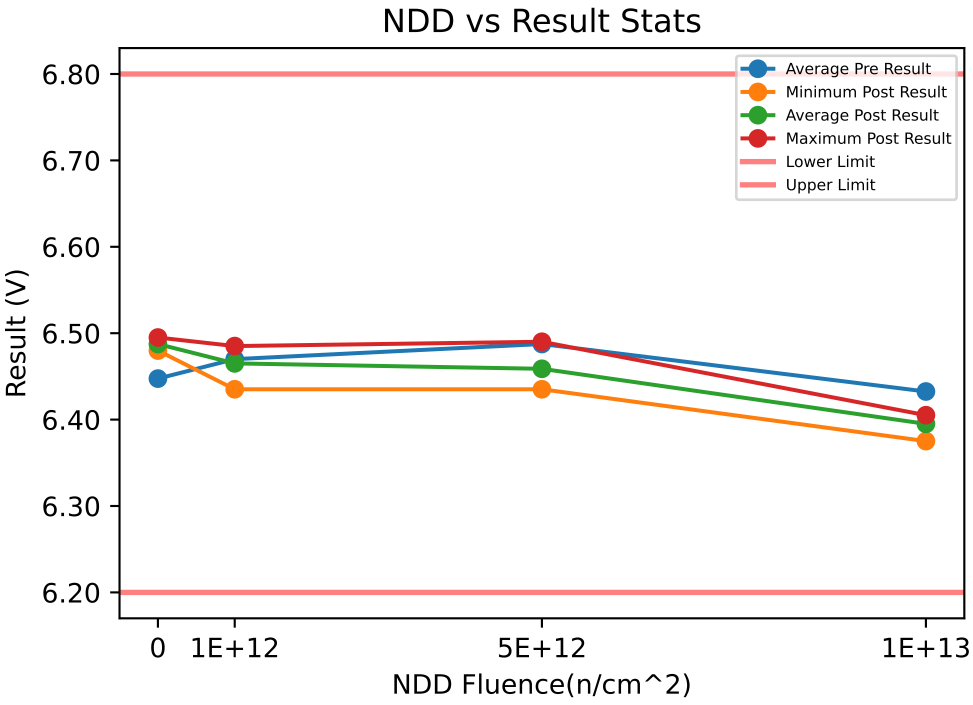
Test Results (Lower Limit = 3.8, Upper Limit = 4.3 (V))

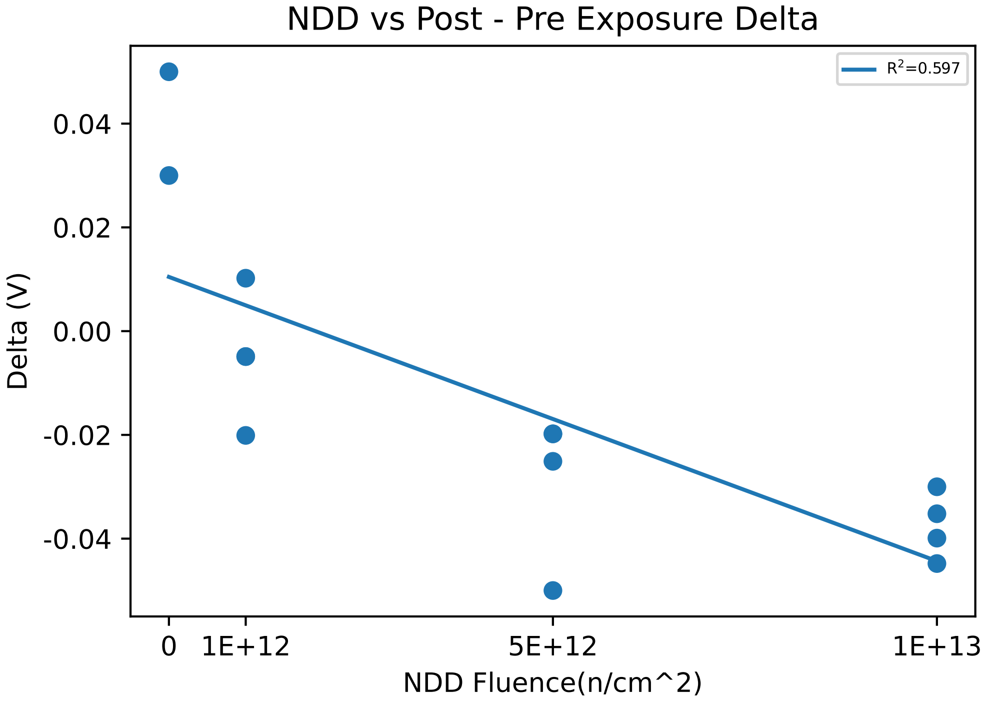
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	4.0701	4.0899	0.0198
2	0	Correlation	4.0599	4.075	0.0151
30	1e+12	NDD unbiased	4.0651	4.0599	-0.0052
31	1e+12	NDD unbiased	4.0599	4.0599	0
32	1e+12	NDD unbiased	4.05	4.045	-0.005
33	1e+12	NDD unbiased	4.05	4.05	0
44	5e+12	NDD unbiased	4.0899	4.08	-0.0099
45	5e+12	NDD unbiased	4.075	4.075	0
46	5e+12	NDD unbiased	4.0701	4.0549	-0.0152
47	5e+12	NDD unbiased	4.0899	4.075	-0.0149
50	1e+13	NDD unbiased	4.0549	4.0299	-0.025
51	1e+13	NDD unbiased	4.0599	4.0401	-0.0198
52	1e+13	NDD unbiased	4.0549	4.0299	-0.025
53	1e+13	NDD unbiased	4.0651	4.0401	-0.025

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.0599	4.065	4.0701	0.0072125	4.075	4.0824	4.0899	0.010536	0.0151	0.01745	0.0198	0.0033234
1e+12	4.05	4.0563	4.0651	0.0075226	4.045	4.0537	4.0599	0.0074445	-0.0052	-0.00255	0	0.0029456
5e+12	4.0701	4.0812	4.0899	0.010215	4.0549	4.0712	4.08	0.011136	-0.0152	-0.01	0	0.007096
1e+13	4.0549	4.0587	4.0651	0.0048744	4.0299	4.035	4.0401	0.005889	-0.025	-0.0237	-0.0198	0.0026

Device Test: 80.4 V_BP7L_TH_RISE(_UVLO BP7L Rise Thresh VIN_10V)


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

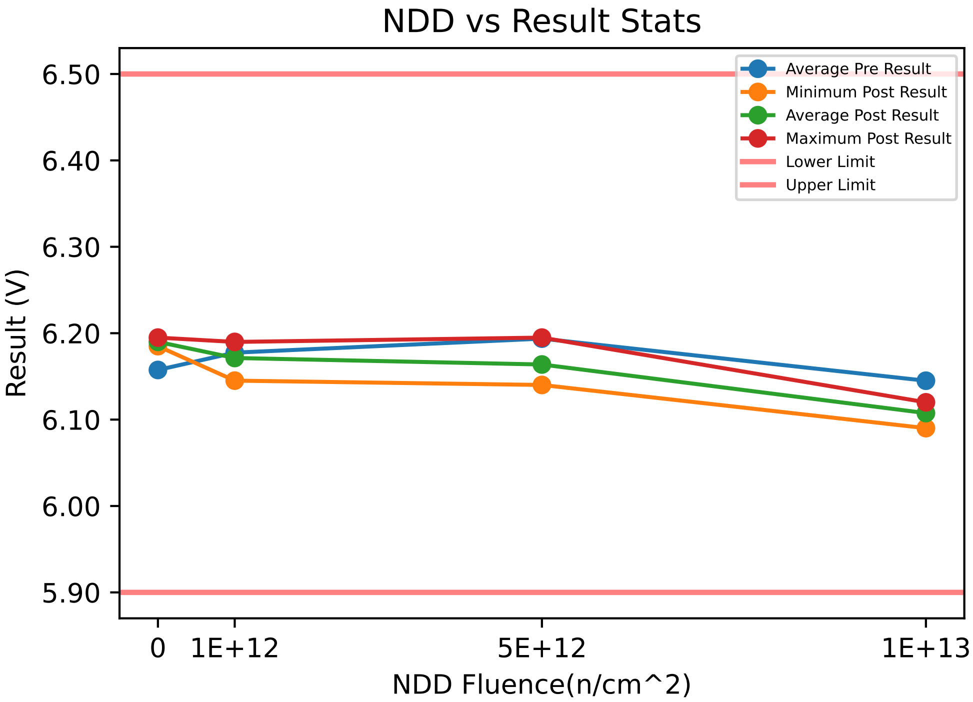
Test Results (Lower Limit = 6.2, Upper Limit = 6.8 (V))

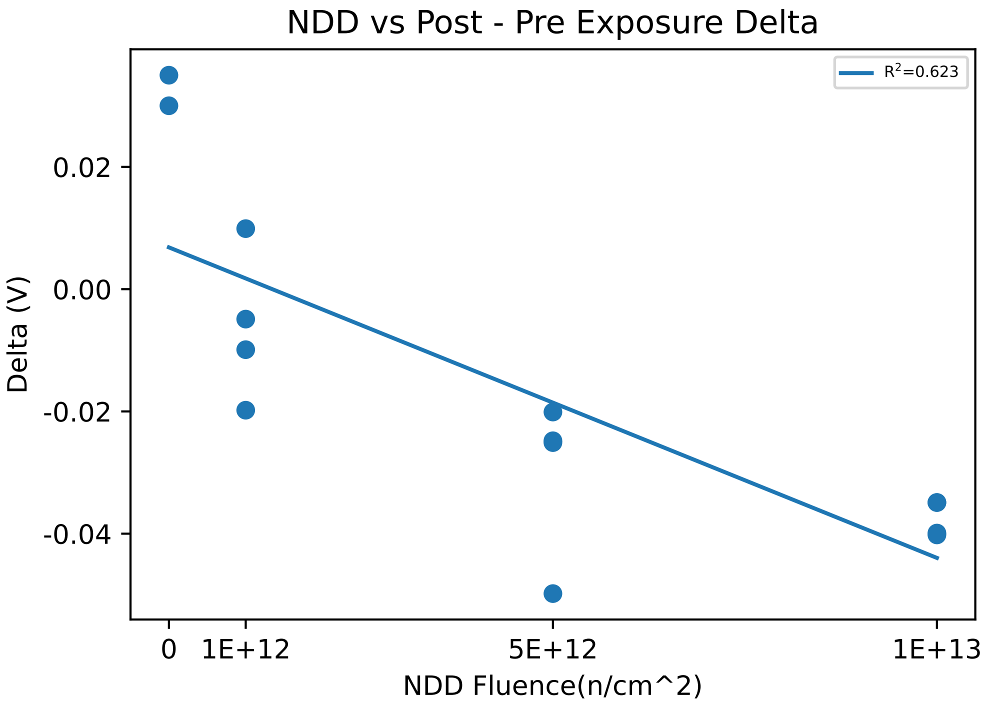
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	6.4499	6.4799	0.03
2	0	Correlation	6.445	6.495	0.05
30	1e+12	NDD unbiased	6.4901	6.47	-0.0201
31	1e+12	NDD unbiased	6.4749	6.4851	0.0102
32	1e+12	NDD unbiased	6.4749	6.47	-0.0049
33	1e+12	NDD unbiased	6.44	6.4351	-0.0049
44	5e+12	NDD unbiased	6.5	6.4749	-0.0251
45	5e+12	NDD unbiased	6.4851	6.4351	-0.05
46	5e+12	NDD unbiased	6.5099	6.4901	-0.0198
47	5e+12	NDD unbiased	6.4549	6.4351	-0.0198
50	1e+13	NDD unbiased	6.4301	6.3949	-0.0352
51	1e+13	NDD unbiased	6.415	6.3751	-0.0399
52	1e+13	NDD unbiased	6.4351	6.4051	-0.03
53	1e+13	NDD unbiased	6.4499	6.4051	-0.0448

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	6.445	6.4474	6.4499	0.0034648	6.4799	6.4874	6.495	0.010677	0.03	0.04	0.05	0.014142
1e+12	6.44	6.47	6.4901	0.021229	6.4351	6.465	6.4851	0.021198	-0.0201	-0.004925	0.0102	0.01237
5e+12	6.4549	6.4875	6.5099	0.02399	6.4351	6.4588	6.4901	0.028061	-0.05	-0.028675	-0.0198	0.014435
1e+13	6.415	6.4325	6.4499	0.014394	6.3751	6.395	6.4051	0.014142	-0.0448	-0.037475	-0.03	0.00634

Device Test: 80.5 V_BP7L_TH_FALL(_UVLO BP7L Fall Thresh VIN_10V)





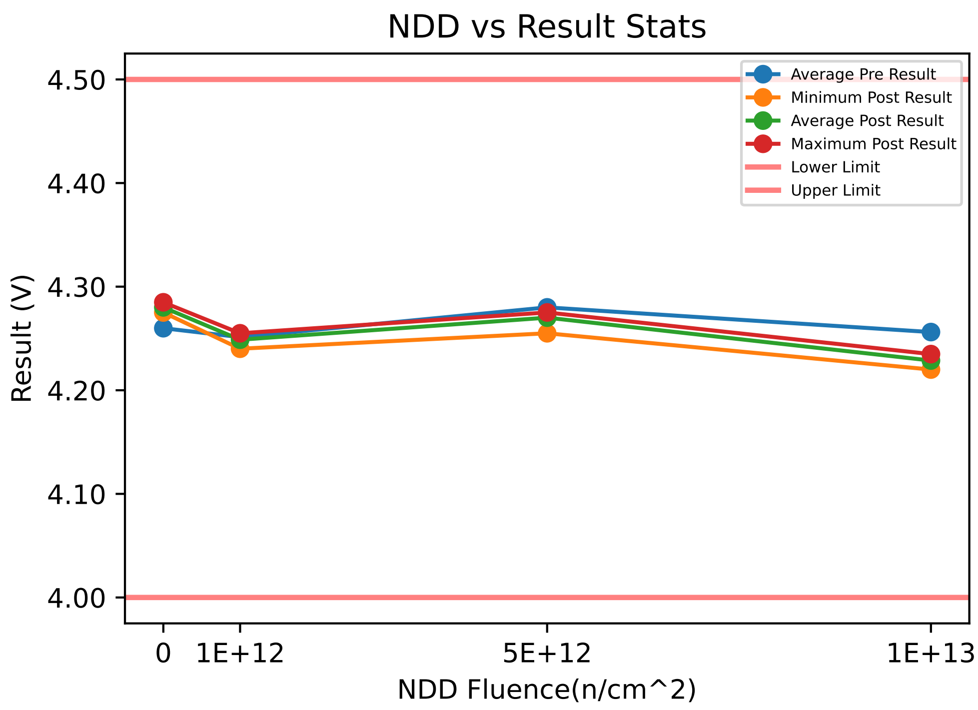
Test Results (Lower Limit = 5.9, Upper Limit = 6.5 (V))

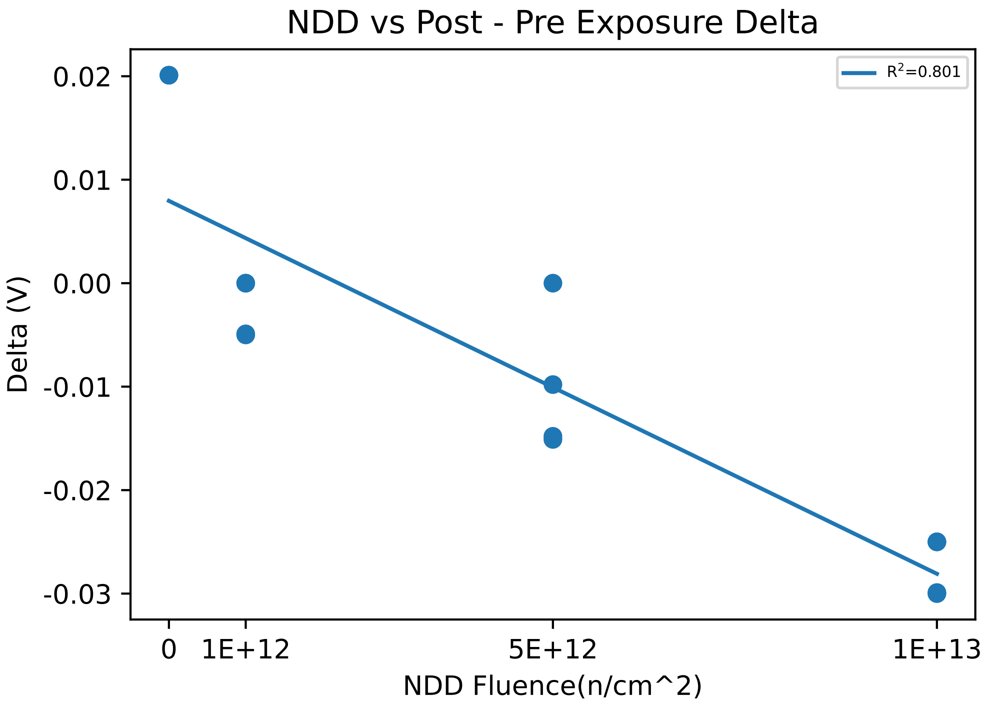
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	6.155	6.185	0.03
2	0	Correlation	6.1599	6.1949	0.035
30	1e+12	NDD unbiased	6.1949	6.1751	-0.0198
31	1e+12	NDD unbiased	6.18	6.1899	0.0099
32	1e+12	NDD unbiased	6.185	6.1751	-0.0099
33	1e+12	NDD unbiased	6.15	6.1451	-0.0049
44	5e+12	NDD unbiased	6.2051	6.18	-0.0251
45	5e+12	NDD unbiased	6.1899	6.1401	-0.0498
46	5e+12	NDD unbiased	6.215	6.1949	-0.0201
47	5e+12	NDD unbiased	6.1649	6.1401	-0.0248
50	1e+13	NDD unbiased	6.1451	6.1049	-0.0402
51	1e+13	NDD unbiased	6.125	6.0901	-0.0349
52	1e+13	NDD unbiased	6.15	6.1151	-0.0349
53	1e+13	NDD unbiased	6.1599	6.12	-0.0399

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	6.155	6.1575	6.1599	0.0034648	6.185	6.1899	6.1949	0.0070004	0.03	0.0325	0.035	0.0035355
1e+12	6.15	6.1775	6.1949	0.019335	6.1451	6.1713	6.1899	0.018809	-0.0198	-0.006175	0.0099	0.012377
5e+12	6.1649	6.1937	6.215	0.021814	6.1401	6.1638	6.1949	0.028006	-0.0498	-0.02995	-0.0201	0.01343
1e+13	6.125	6.145	6.1599	0.014686	6.0901	6.1075	6.12	0.01321	-0.0402	-0.037475	-0.0349	0.0029759

Device Test: 81.1 V_BP5L_TH_RISE(_UVLO BP5L Rise Thresh VIN_12V)





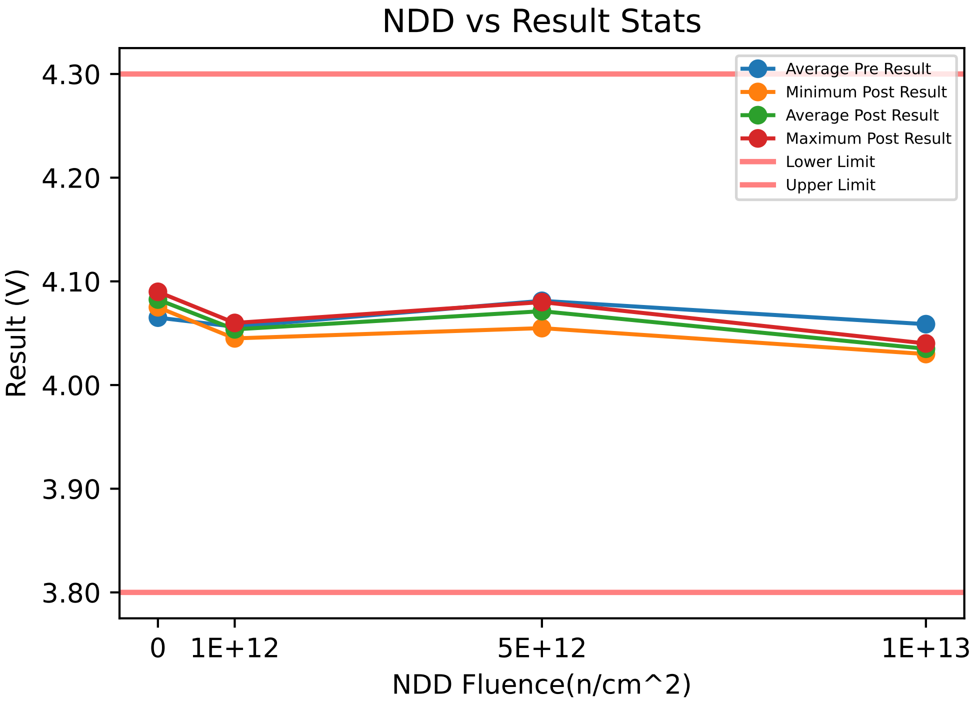
Test Results (Lower Limit = 4.0, Upper Limit = 4.5 (V))

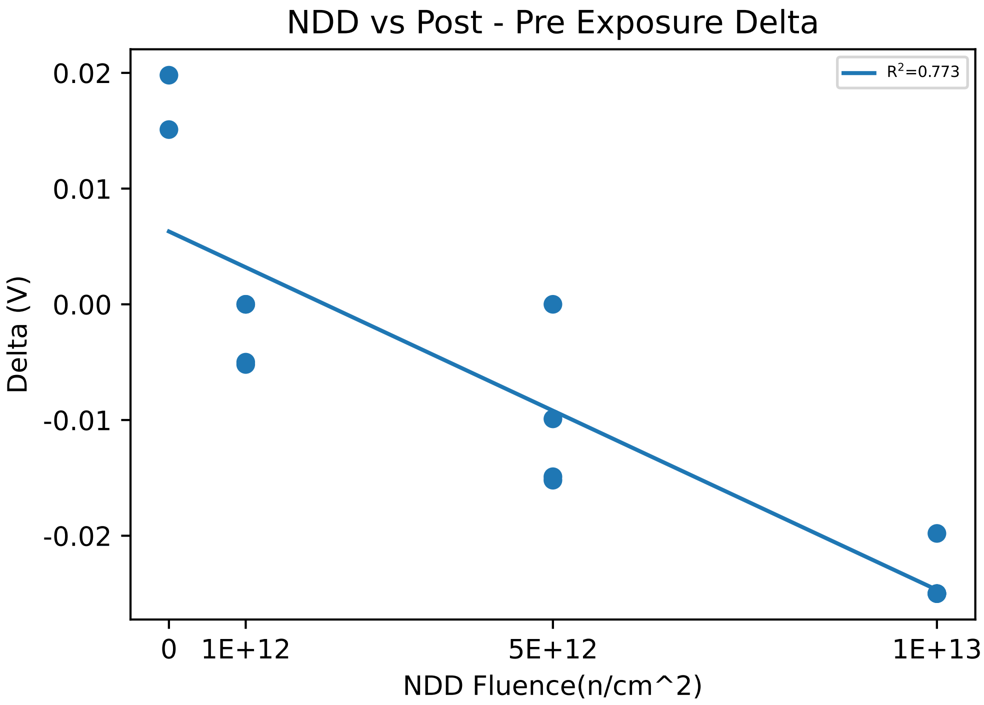
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	4.2648	4.2849	0.0201
2	0	Correlation	4.255	4.2751	0.0201
30	1e+12	NDD unbiased	4.2599	4.255	-0.0049
31	1e+12	NDD unbiased	4.255	4.255	0
32	1e+12	NDD unbiased	4.2451	4.2401	-0.005
33	1e+12	NDD unbiased	4.2451	4.2451	0
44	5e+12	NDD unbiased	4.2849	4.2751	-0.0098
45	5e+12	NDD unbiased	4.2751	4.2751	0
46	5e+12	NDD unbiased	4.2701	4.255	-0.0151
47	5e+12	NDD unbiased	4.2899	4.2751	-0.0148
50	1e+13	NDD unbiased	4.25	4.22	-0.03
51	1e+13	NDD unbiased	4.2599	4.2349	-0.025
52	1e+13	NDD unbiased	4.25	4.225	-0.025
53	1e+13	NDD unbiased	4.2648	4.2349	-0.0299

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.255	4.2599	4.2648	0.0069296	4.2751	4.28	4.2849	0.0069296	0.0201	0.0201	0.0201	0
1e+12	4.2451	4.2513	4.2599	0.0074056	4.2401	4.2488	4.255	0.0074445	-0.005	-0.002475	0	0.0028582
5e+12	4.2701	4.28	4.2899	0.0090192	4.255	4.2701	4.2751	0.01005	-0.0151	-0.009925	0	0.0070491
1e+13	4.25	4.2562	4.2648	0.0074056	4.22	4.2287	4.2349	0.0074445	-0.03	-0.027475	-0.025	0.0028582

Device Test: 81.2 V_BP5L_TH_FALL(_UVLO BP5L Fall Thresh VIN_12V)





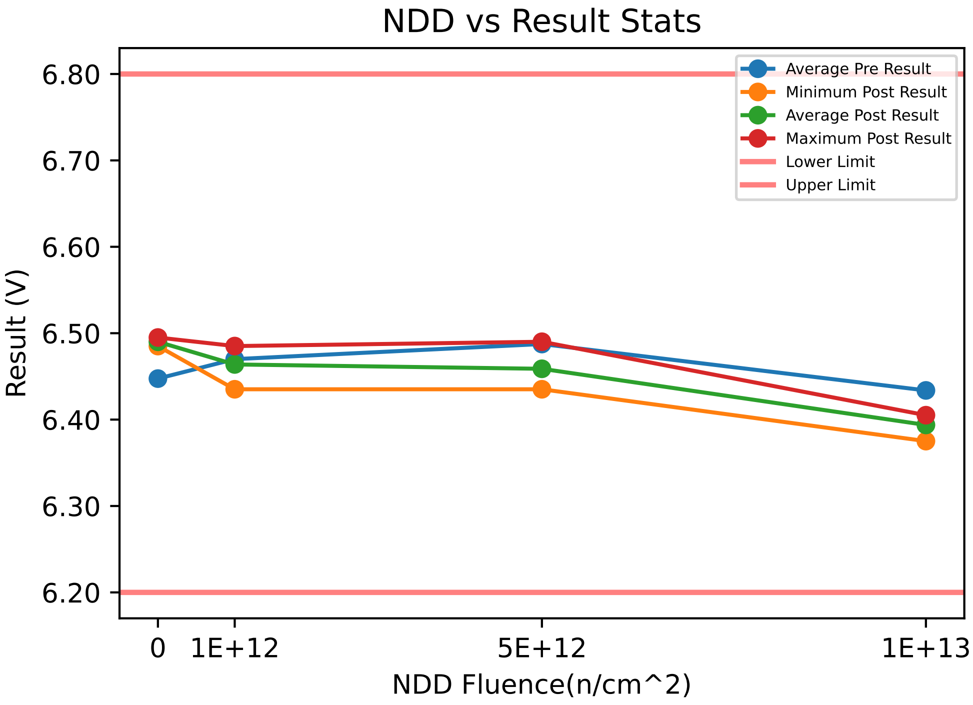
Test Results (Lower Limit = 3.8, Upper Limit = 4.3 (V))

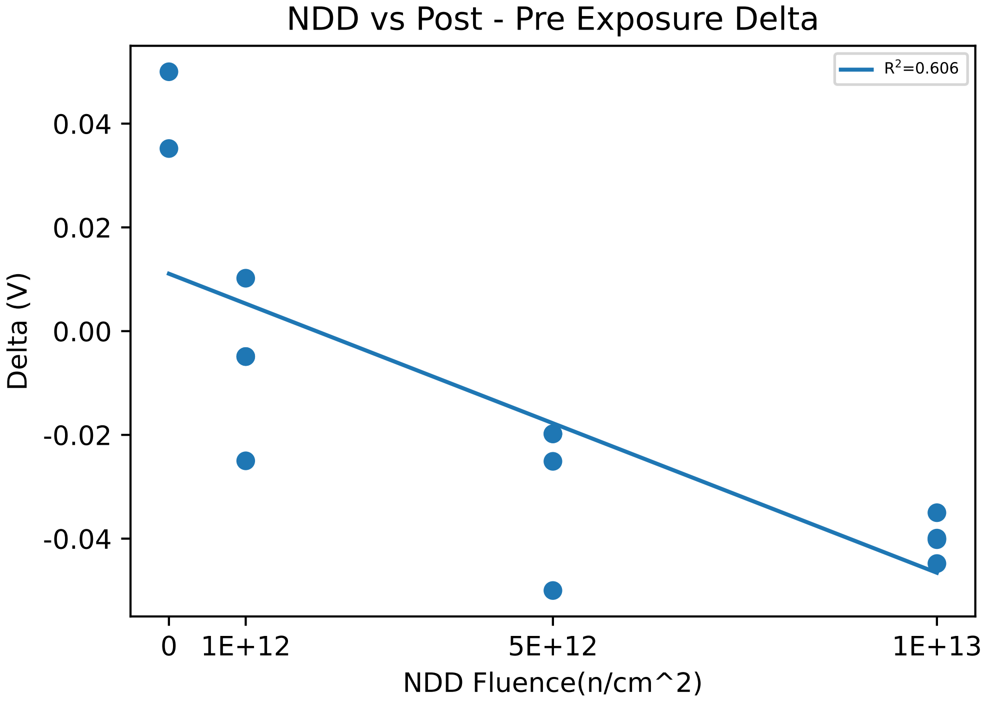
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	4.0701	4.0899	0.0198
2	0	Correlation	4.0599	4.075	0.0151
30	1e+12	NDD unbiased	4.0651	4.0599	-0.0052
31	1e+12	NDD unbiased	4.0599	4.0599	0
32	1e+12	NDD unbiased	4.05	4.045	-0.005
33	1e+12	NDD unbiased	4.05	4.05	0
44	5e+12	NDD unbiased	4.0899	4.08	-0.0099
45	5e+12	NDD unbiased	4.075	4.075	0
46	5e+12	NDD unbiased	4.0701	4.0549	-0.0152
47	5e+12	NDD unbiased	4.0899	4.075	-0.0149
50	1e+13	NDD unbiased	4.0549	4.0299	-0.025
51	1e+13	NDD unbiased	4.0599	4.0401	-0.0198
52	1e+13	NDD unbiased	4.0549	4.0299	-0.025
53	1e+13	NDD unbiased	4.0651	4.0401	-0.025

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.0599	4.065	4.0701	0.0072125	4.075	4.0824	4.0899	0.010536	0.0151	0.01745	0.0198	0.0033234
1e+12	4.05	4.0563	4.0651	0.0075226	4.045	4.0537	4.0599	0.0074445	-0.0052	-0.00255	0	0.0029456
5e+12	4.0701	4.0812	4.0899	0.010215	4.0549	4.0712	4.08	0.011136	-0.0152	-0.01	0	0.007096
1e+13	4.0549	4.0587	4.0651	0.0048744	4.0299	4.035	4.0401	0.005889	-0.025	-0.0237	-0.0198	0.0026

Device Test: 81.4 V_BP7L_TH_RISE(_UVLO BP7L Rise Thresh VIN_12V)


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

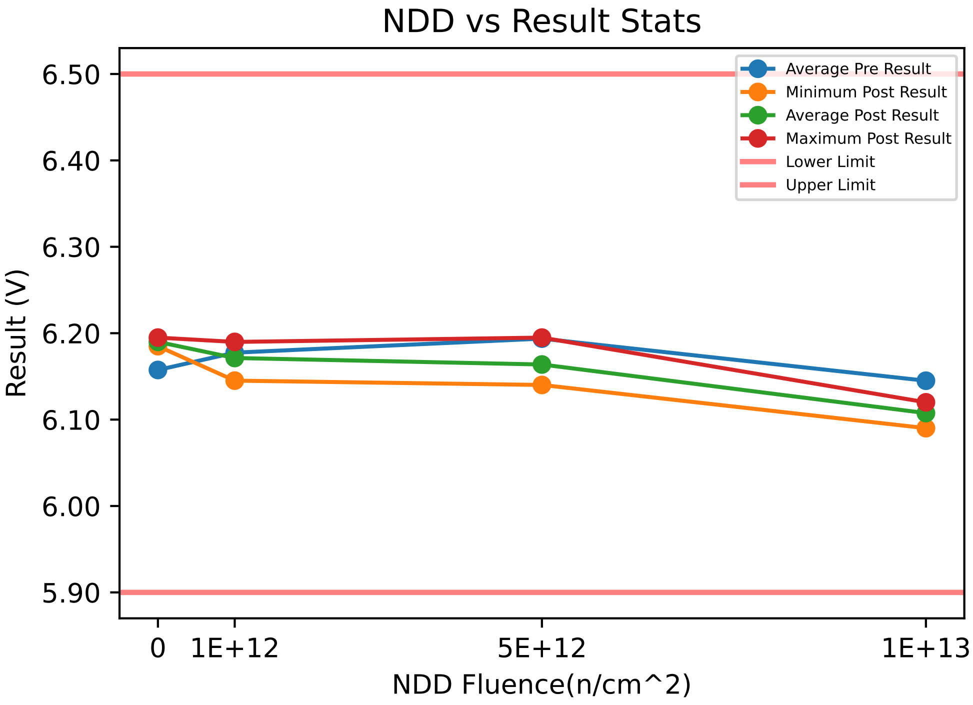
Test Results (Lower Limit = 6.2, Upper Limit = 6.8 (V))

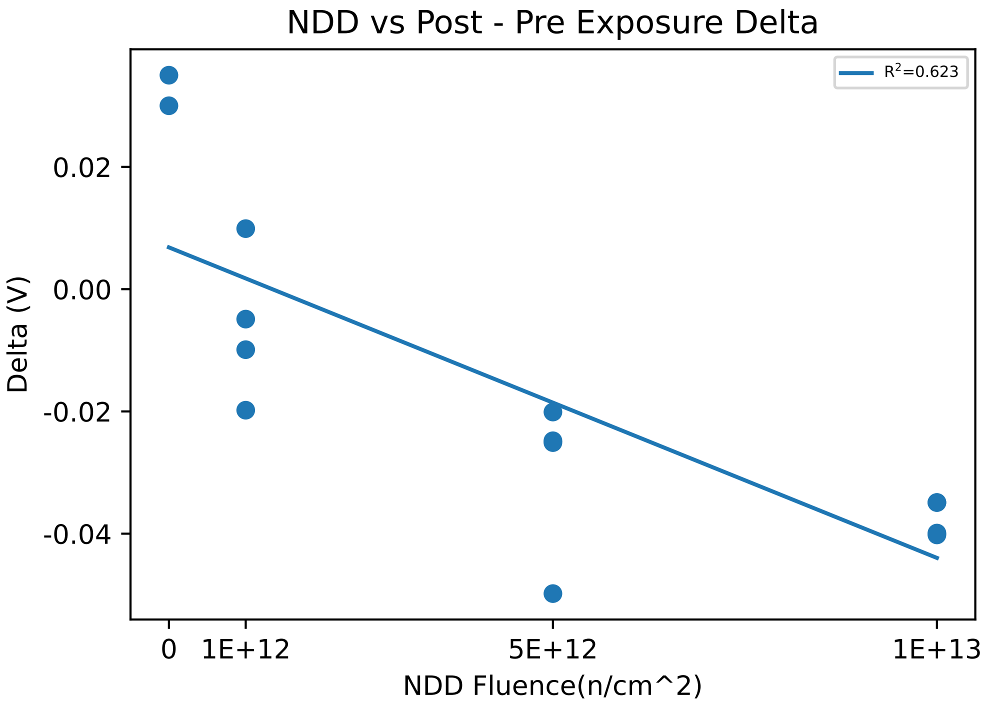
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	6.4499	6.4851	0.0352
2	0	Correlation	6.445	6.495	0.05
30	1e+12	NDD unbiased	6.4901	6.4651	-0.025
31	1e+12	NDD unbiased	6.4749	6.4851	0.0102
32	1e+12	NDD unbiased	6.4749	6.47	-0.0049
33	1e+12	NDD unbiased	6.44	6.4351	-0.0049
44	5e+12	NDD unbiased	6.5	6.4749	-0.0251
45	5e+12	NDD unbiased	6.4851	6.4351	-0.05
46	5e+12	NDD unbiased	6.5099	6.4901	-0.0198
47	5e+12	NDD unbiased	6.4549	6.4351	-0.0198
50	1e+13	NDD unbiased	6.4351	6.3949	-0.0402
51	1e+13	NDD unbiased	6.415	6.3751	-0.0399
52	1e+13	NDD unbiased	6.4351	6.4001	-0.035
53	1e+13	NDD unbiased	6.4499	6.4051	-0.0448

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	6.445	6.4474	6.4499	0.0034648	6.4851	6.4901	6.495	0.0070004	0.0352	0.0426	0.05	0.010465
1e+12	6.44	6.47	6.4901	0.021229	6.4351	6.4638	6.4851	0.020956	-0.025	-0.00615	0.0102	0.014443
5e+12	6.4549	6.4875	6.5099	0.02399	6.4351	6.4588	6.4901	0.028061	-0.05	-0.028675	-0.0198	0.014435
1e+13	6.415	6.4338	6.4499	0.01433	6.3751	6.3938	6.4051	0.013144	-0.0448	-0.039975	-0.035	0.0040036

Device Test: 81.5 V_BP7L_TH_FALL(_UVLO BP7L Fall Thresh VIN_12V)





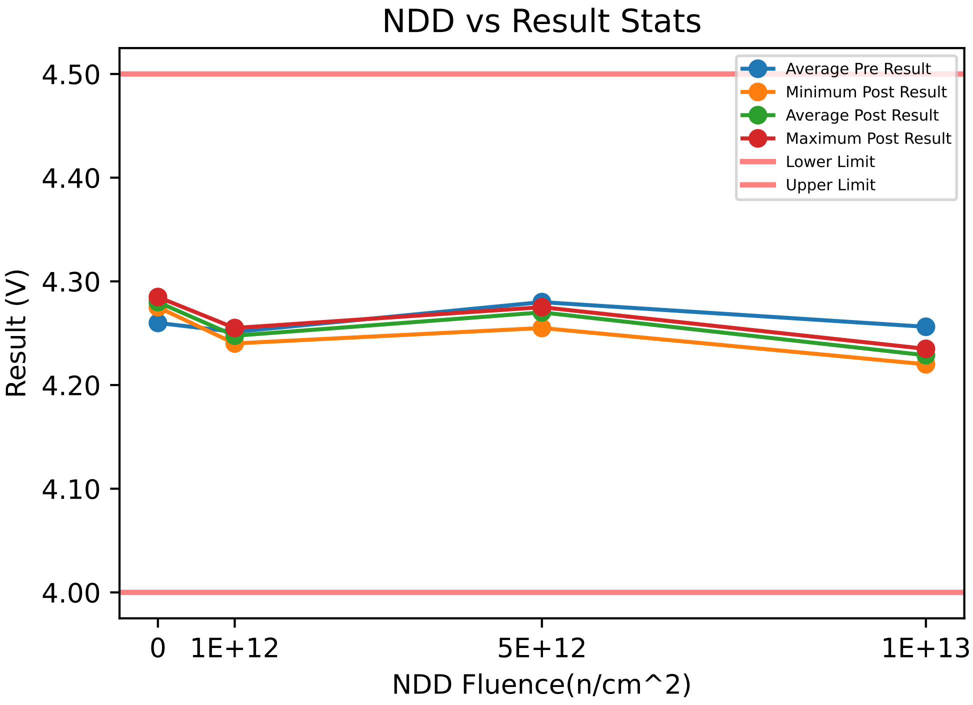
Test Results (Lower Limit = 5.9, Upper Limit = 6.5 (V))

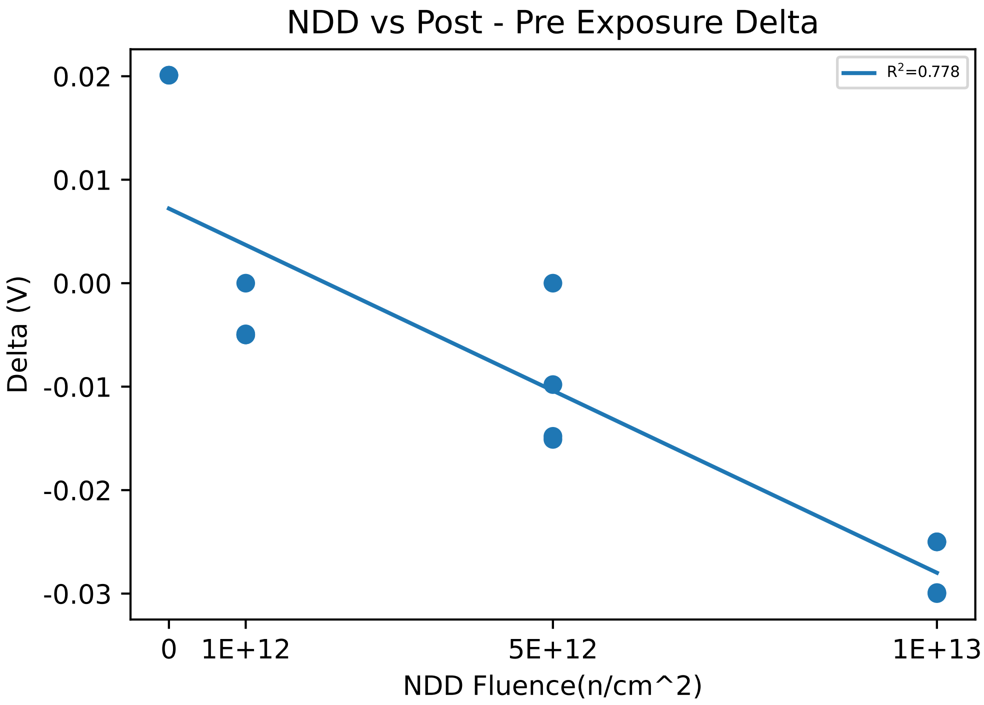
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	6.155	6.185	0.03
2	0	Correlation	6.1599	6.1949	0.035
30	1e+12	NDD unbiased	6.1949	6.1751	-0.0198
31	1e+12	NDD unbiased	6.18	6.1899	0.0099
32	1e+12	NDD unbiased	6.185	6.1751	-0.0099
33	1e+12	NDD unbiased	6.15	6.1451	-0.0049
44	5e+12	NDD unbiased	6.2051	6.18	-0.0251
45	5e+12	NDD unbiased	6.1899	6.1401	-0.0498
46	5e+12	NDD unbiased	6.215	6.1949	-0.0201
47	5e+12	NDD unbiased	6.1649	6.1401	-0.0248
50	1e+13	NDD unbiased	6.1451	6.1049	-0.0402
51	1e+13	NDD unbiased	6.125	6.0901	-0.0349
52	1e+13	NDD unbiased	6.15	6.1151	-0.0349
53	1e+13	NDD unbiased	6.1599	6.12	-0.0399

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	6.155	6.1575	6.1599	0.0034648	6.185	6.1899	6.1949	0.0070004	0.03	0.0325	0.035	0.0035355
1e+12	6.15	6.1775	6.1949	0.019335	6.1451	6.1713	6.1899	0.018809	-0.0198	-0.006175	0.0099	0.012377
5e+12	6.1649	6.1937	6.215	0.021814	6.1401	6.1638	6.1949	0.028006	-0.0498	-0.02995	-0.0201	0.01343
1e+13	6.125	6.145	6.1599	0.014686	6.0901	6.1075	6.12	0.01321	-0.0402	-0.037475	-0.0349	0.0029759

Device Test: 82.1 V_BP5L_TH_RISE(_UVLO BP5L Rise Thresh VIN_14V)





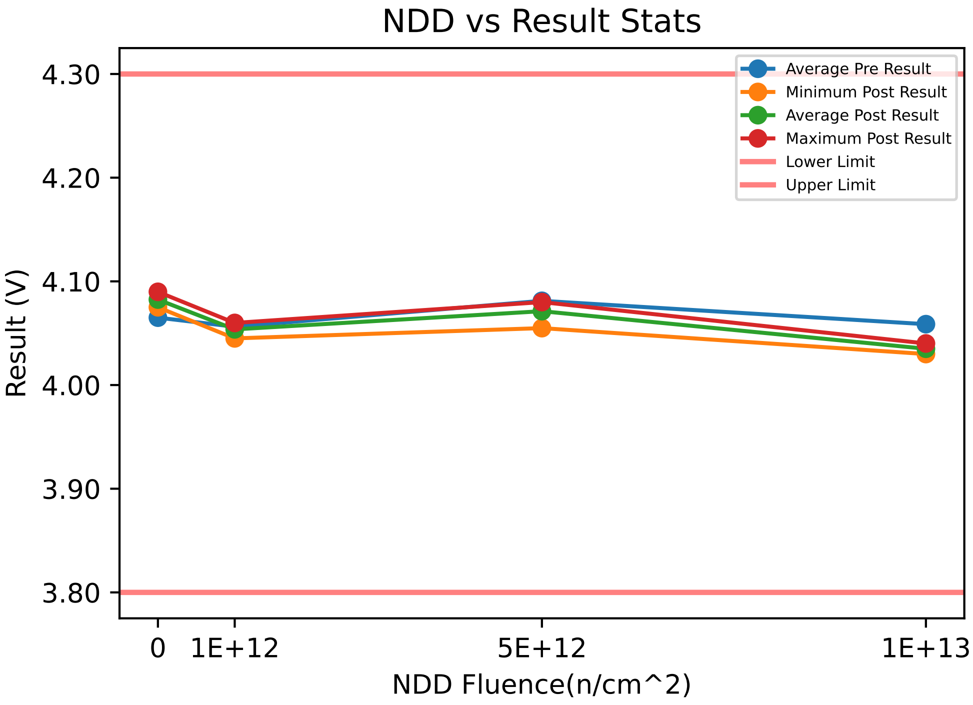
Test Results (Lower Limit = 4.0, Upper Limit = 4.5 (V))

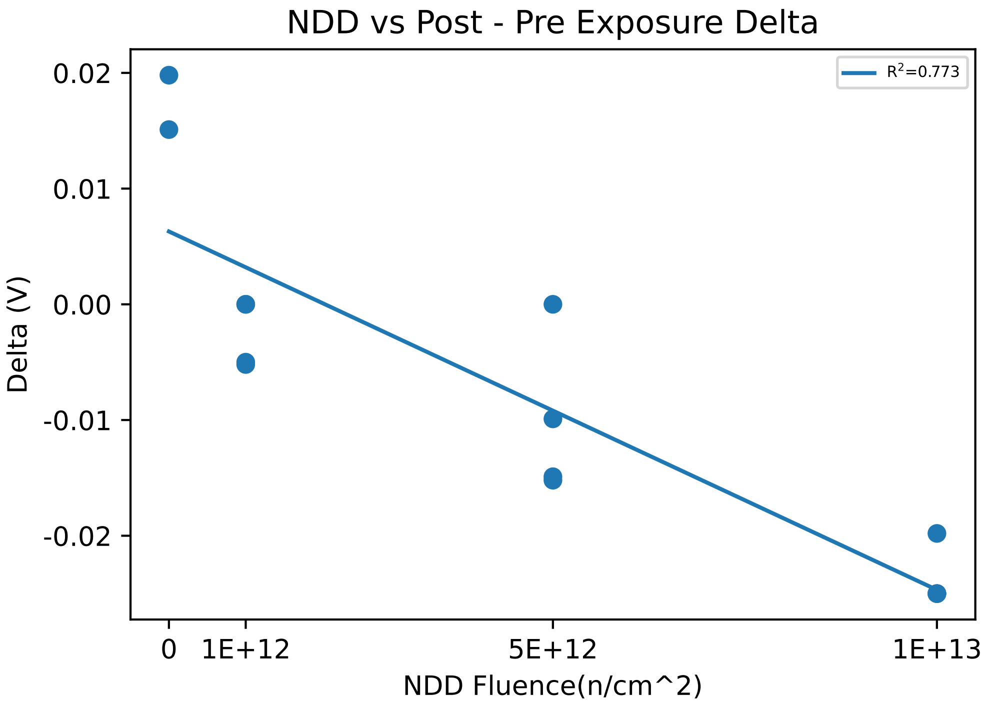
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	4.2648	4.2849	0.0201
2	0	Correlation	4.255	4.2751	0.0201
30	1e+12	NDD unbiased	4.2599	4.255	-0.0049
31	1e+12	NDD unbiased	4.255	4.255	0
32	1e+12	NDD unbiased	4.2451	4.2401	-0.005
33	1e+12	NDD unbiased	4.2451	4.2401	-0.005
44	5e+12	NDD unbiased	4.2849	4.2751	-0.0098
45	5e+12	NDD unbiased	4.2751	4.2751	0
46	5e+12	NDD unbiased	4.2701	4.255	-0.0151
47	5e+12	NDD unbiased	4.2899	4.2751	-0.0148
50	1e+13	NDD unbiased	4.25	4.22	-0.03
51	1e+13	NDD unbiased	4.2599	4.2349	-0.025
52	1e+13	NDD unbiased	4.25	4.225	-0.025
53	1e+13	NDD unbiased	4.2648	4.2349	-0.0299

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.255	4.2599	4.2648	0.0069296	4.2751	4.28	4.2849	0.0069296	0.0201	0.0201	0.0201	0
1e+12	4.2451	4.2513	4.2599	0.0074056	4.2401	4.2476	4.255	0.0086025	-0.005	-0.003725	0	0.0024838
5e+12	4.2701	4.28	4.2899	0.0090192	4.255	4.2701	4.2751	0.01005	-0.0151	-0.009925	0	0.0070491
1e+13	4.25	4.2562	4.2648	0.0074056	4.22	4.2287	4.2349	0.0074445	-0.03	-0.027475	-0.025	0.0028582

Device Test: 82.2 V_BP5L_TH_FALL(_UVLO BP5L Fall Thresh VIN_14V)


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

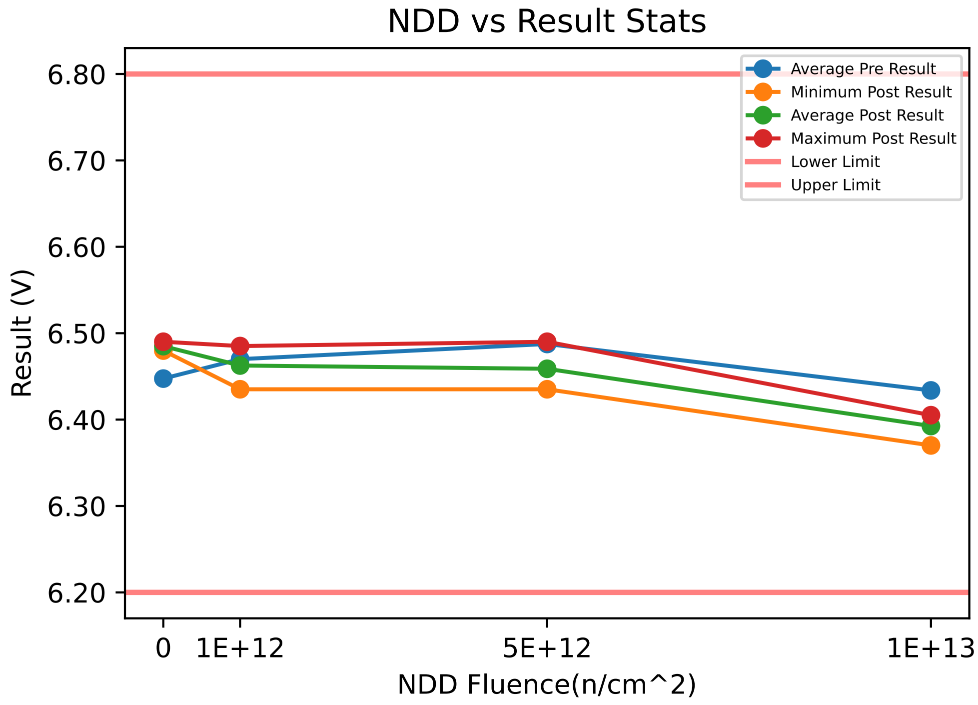
Test Results (Lower Limit = 3.8, Upper Limit = 4.3 (V))

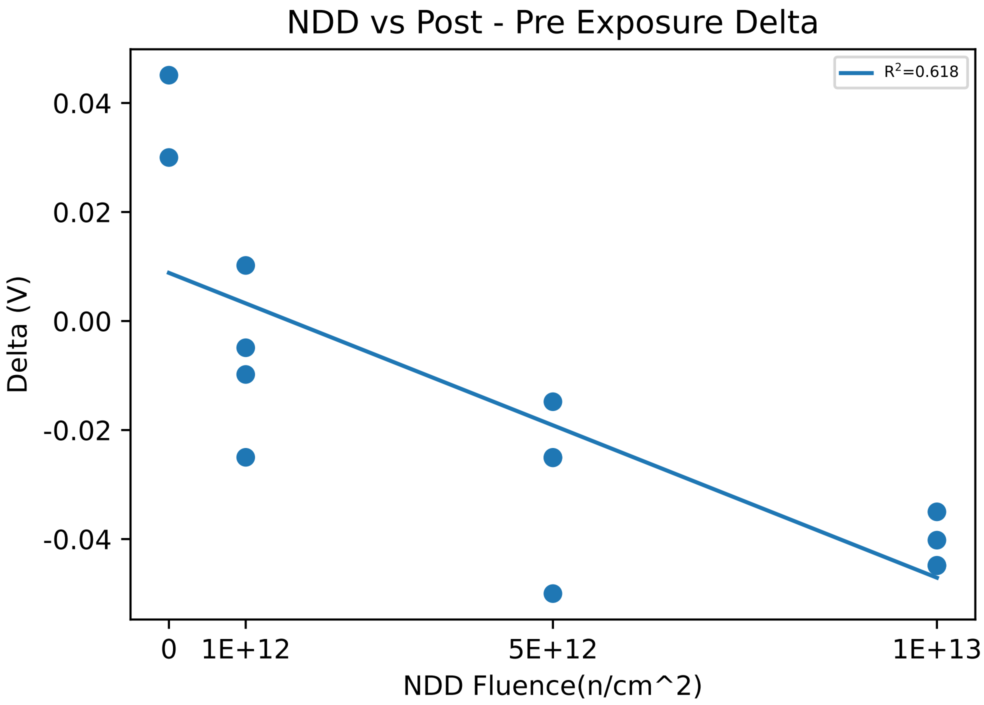
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	4.0701	4.0899	0.0198
2	0	Correlation	4.0599	4.075	0.0151
30	1e+12	NDD unbiased	4.0651	4.0599	-0.0052
31	1e+12	NDD unbiased	4.0599	4.0599	0
32	1e+12	NDD unbiased	4.05	4.045	-0.005
33	1e+12	NDD unbiased	4.05	4.05	0
44	5e+12	NDD unbiased	4.0899	4.08	-0.0099
45	5e+12	NDD unbiased	4.075	4.075	0
46	5e+12	NDD unbiased	4.0701	4.0549	-0.0152
47	5e+12	NDD unbiased	4.0899	4.075	-0.0149
50	1e+13	NDD unbiased	4.0549	4.0299	-0.025
51	1e+13	NDD unbiased	4.0599	4.0401	-0.0198
52	1e+13	NDD unbiased	4.0549	4.0299	-0.025
53	1e+13	NDD unbiased	4.0651	4.0401	-0.025

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.0599	4.065	4.0701	0.0072125	4.075	4.0824	4.0899	0.010536	0.0151	0.01745	0.0198	0.0033234
1e+12	4.05	4.0563	4.0651	0.0075226	4.045	4.0537	4.0599	0.0074445	-0.0052	-0.00255	0	0.0029456
5e+12	4.0701	4.0812	4.0899	0.010215	4.0549	4.0712	4.08	0.011136	-0.0152	-0.01	0	0.007096
1e+13	4.0549	4.0587	4.0651	0.0048744	4.0299	4.035	4.0401	0.005889	-0.025	-0.0237	-0.0198	0.0026

Device Test: 82.4 V_BP7L_TH_RISE(_UVLO BP7L Rise Thresh VIN_14V)


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

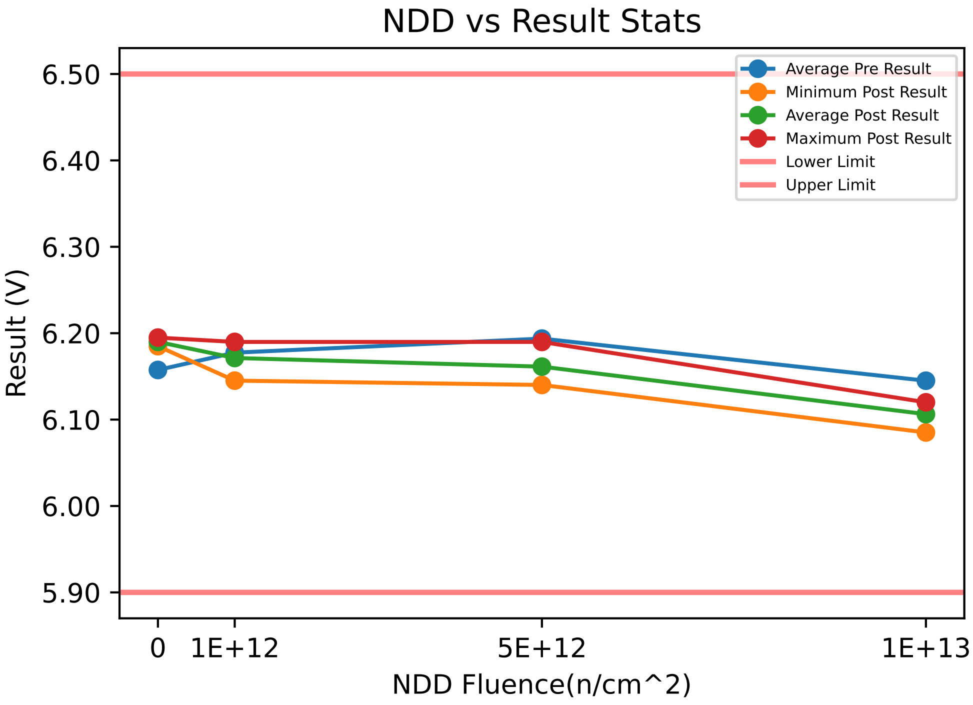
Test Results (Lower Limit = 6.2, Upper Limit = 6.8 (V))

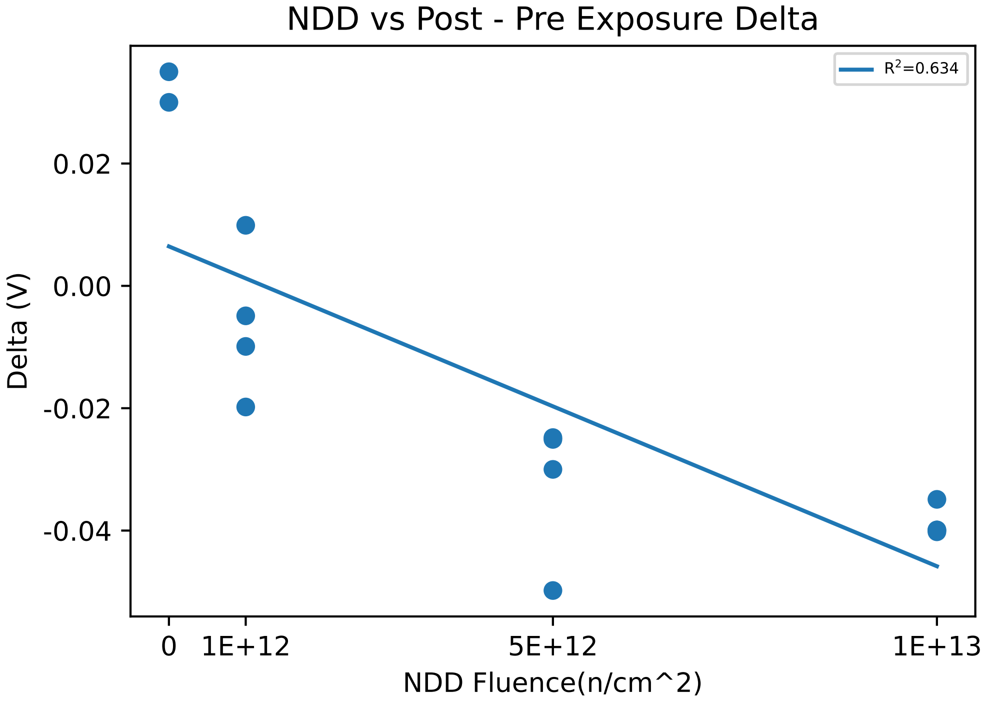
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	6.4499	6.4799	0.03
2	0	Correlation	6.445	6.4901	0.0451
30	1e+12	NDD unbiased	6.4901	6.4651	-0.025
31	1e+12	NDD unbiased	6.4749	6.4851	0.0102
32	1e+12	NDD unbiased	6.4749	6.4651	-0.0098
33	1e+12	NDD unbiased	6.44	6.4351	-0.0049
44	5e+12	NDD unbiased	6.5	6.4749	-0.0251
45	5e+12	NDD unbiased	6.4851	6.4351	-0.05
46	5e+12	NDD unbiased	6.5049	6.4901	-0.0148
47	5e+12	NDD unbiased	6.4601	6.4351	-0.025
50	1e+13	NDD unbiased	6.4351	6.3949	-0.0402
51	1e+13	NDD unbiased	6.415	6.3701	-0.0449
52	1e+13	NDD unbiased	6.4351	6.4001	-0.035
53	1e+13	NDD unbiased	6.4499	6.4051	-0.0448

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	6.445	6.4474	6.4499	0.0034648	6.4799	6.485	6.4901	0.0072125	0.03	0.03755	0.0451	0.010677
1e+12	6.44	6.47	6.4901	0.021229	6.4351	6.4626	6.4851	0.020616	-0.025	-0.007375	0.0102	0.014509
5e+12	6.4601	6.4875	6.5049	0.020129	6.4351	6.4588	6.4901	0.028061	-0.05	-0.028725	-0.0148	0.014984
1e+13	6.415	6.4338	6.4499	0.01433	6.3701	6.3925	6.4051	0.015535	-0.0449	-0.041225	-0.035	0.0046935

Device Test: 82.5 V_BP7L_TH_FALL(_UVLO BP7L Fall Thresh VIN_14V)





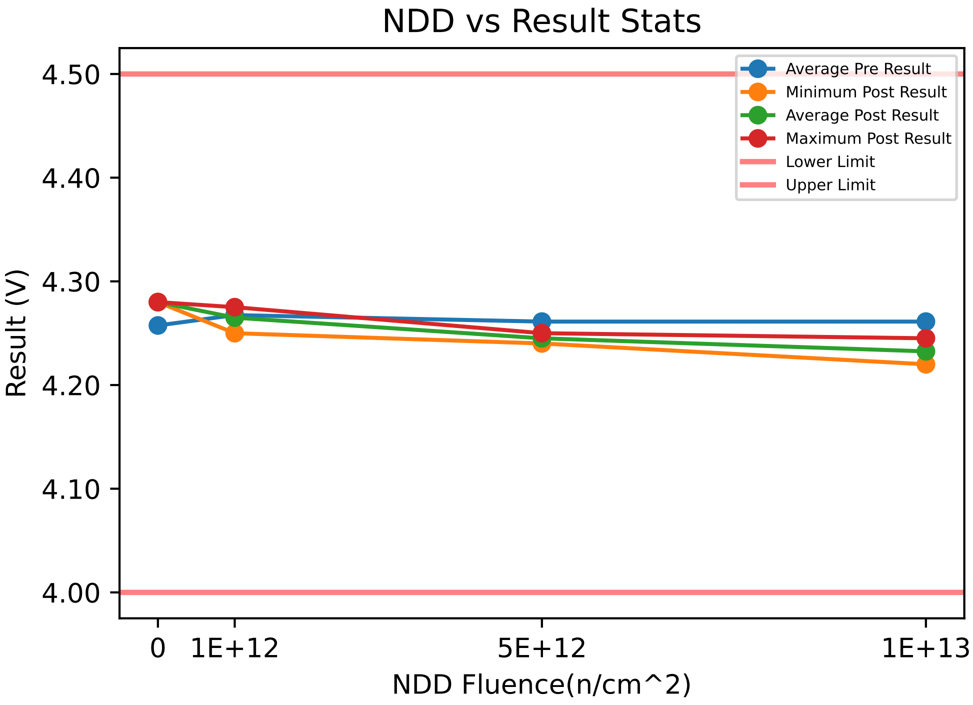
Test Results (Lower Limit = 5.9, Upper Limit = 6.5 (V))

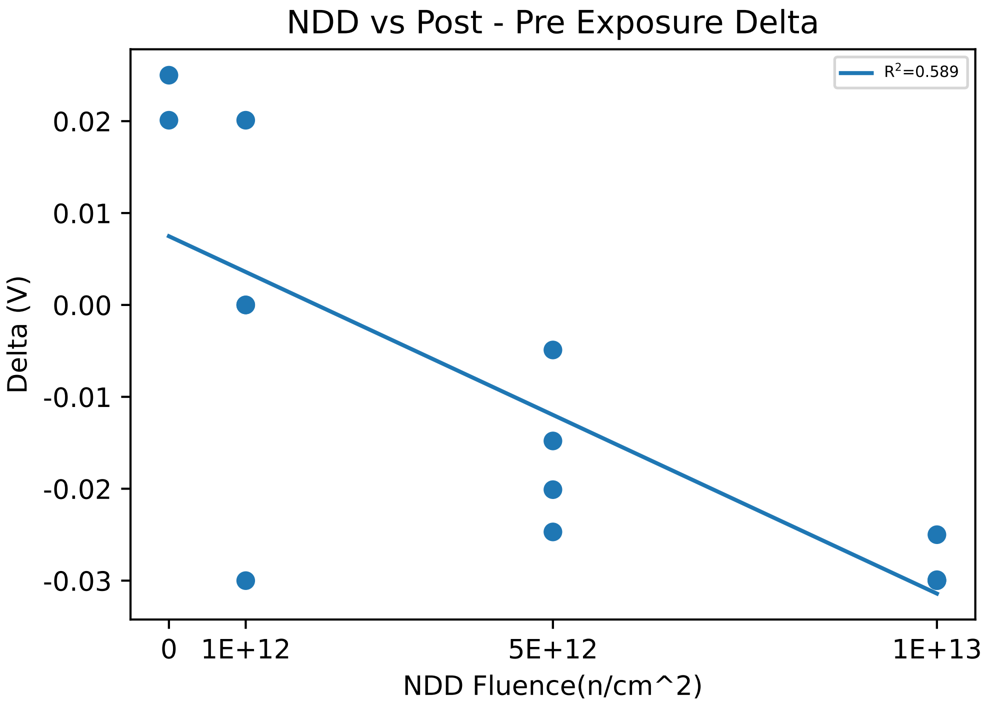
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	6.155	6.185	0.03
2	0	Correlation	6.1599	6.1949	0.035
30	1e+12	NDD unbiased	6.1949	6.1751	-0.0198
31	1e+12	NDD unbiased	6.18	6.1899	0.0099
32	1e+12	NDD unbiased	6.185	6.1751	-0.0099
33	1e+12	NDD unbiased	6.15	6.1451	-0.0049
44	5e+12	NDD unbiased	6.2051	6.1751	-0.03
45	5e+12	NDD unbiased	6.1899	6.1401	-0.0498
46	5e+12	NDD unbiased	6.215	6.1899	-0.0251
47	5e+12	NDD unbiased	6.1649	6.1401	-0.0248
50	1e+13	NDD unbiased	6.1451	6.1049	-0.0402
51	1e+13	NDD unbiased	6.125	6.0851	-0.0399
52	1e+13	NDD unbiased	6.15	6.1151	-0.0349
53	1e+13	NDD unbiased	6.1599	6.12	-0.0399

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	6.155	6.1575	6.1599	0.0034648	6.185	6.1899	6.1949	0.0070004	0.03	0.0325	0.035	0.0035355
1e+12	6.15	6.1775	6.1949	0.019335	6.1451	6.1713	6.1899	0.018809	-0.0198	-0.006175	0.0099	0.012377
5e+12	6.1649	6.1937	6.215	0.021814	6.1401	6.1613	6.1899	0.025214	-0.0498	-0.032425	-0.0248	0.011826
1e+13	6.125	6.145	6.1599	0.014686	6.0851	6.1063	6.12	0.015455	-0.0402	-0.038725	-0.0349	0.0025539

Device Test: 85.1 V_BP5H_TH_RISE(_UVLO BP5H Rise Thresh VIN_10V)


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

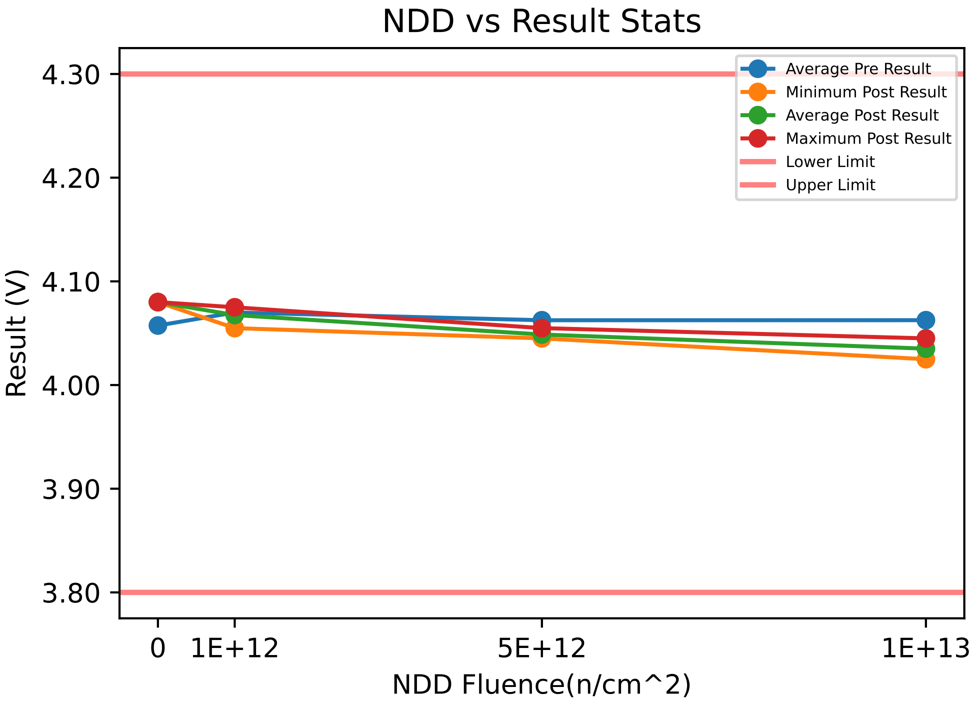
Test Results (Lower Limit = 4.0, Upper Limit = 4.5 (V))

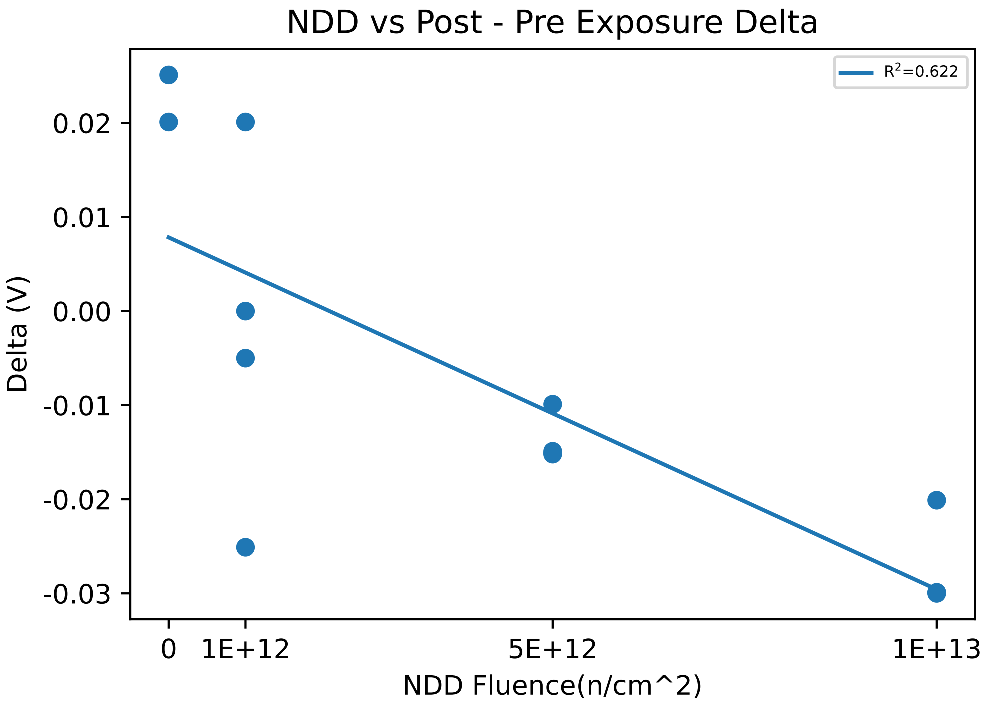
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	4.2599	4.28	0.0201
2	0	Correlation	4.255	4.28	0.025
30	1e+12	NDD unbiased	4.28	4.25	-0.03
31	1e+12	NDD unbiased	4.25	4.2701	0.0201
32	1e+12	NDD unbiased	4.2751	4.2751	0
33	1e+12	NDD unbiased	4.2648	4.2648	0
44	5e+12	NDD unbiased	4.2648	4.2401	-0.0247
45	5e+12	NDD unbiased	4.25	4.2451	-0.0049
46	5e+12	NDD unbiased	4.2701	4.25	-0.0201
47	5e+12	NDD unbiased	4.2599	4.2451	-0.0148
50	1e+13	NDD unbiased	4.2599	4.2299	-0.03
51	1e+13	NDD unbiased	4.2648	4.2349	-0.0299
52	1e+13	NDD unbiased	4.2701	4.2451	-0.025
53	1e+13	NDD unbiased	4.25	4.22	-0.03

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.255	4.2575	4.2599	0.0034648	4.28	4.28	4.28	0	0.0201	0.02255	0.025	0.0034648
1e+12	4.25	4.2675	4.28	0.013261	4.25	4.265	4.2751	0.010848	-0.03	-0.002475	0.0201	0.020652
5e+12	4.25	4.2612	4.2701	0.0085499	4.2401	4.2451	4.25	0.0040418	-0.0247	-0.016125	-0.0049	0.0085066
1e+13	4.25	4.2612	4.2701	0.0085499	4.22	4.2325	4.2451	0.010449	-0.03	-0.028725	-0.025	0.0024838

Device Test: 85.2 V_BP5H_TH_FALL(_UVLO BP5H Fall Thresh VIN_10V)


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

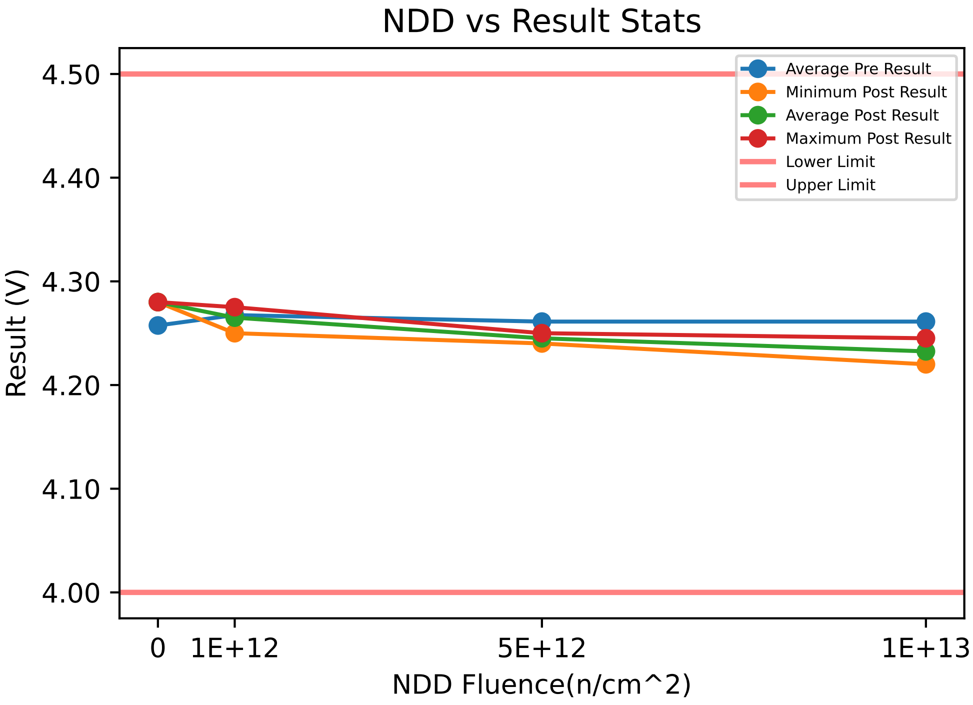
Test Results (Lower Limit = 3.8, Upper Limit = 4.3 (V))

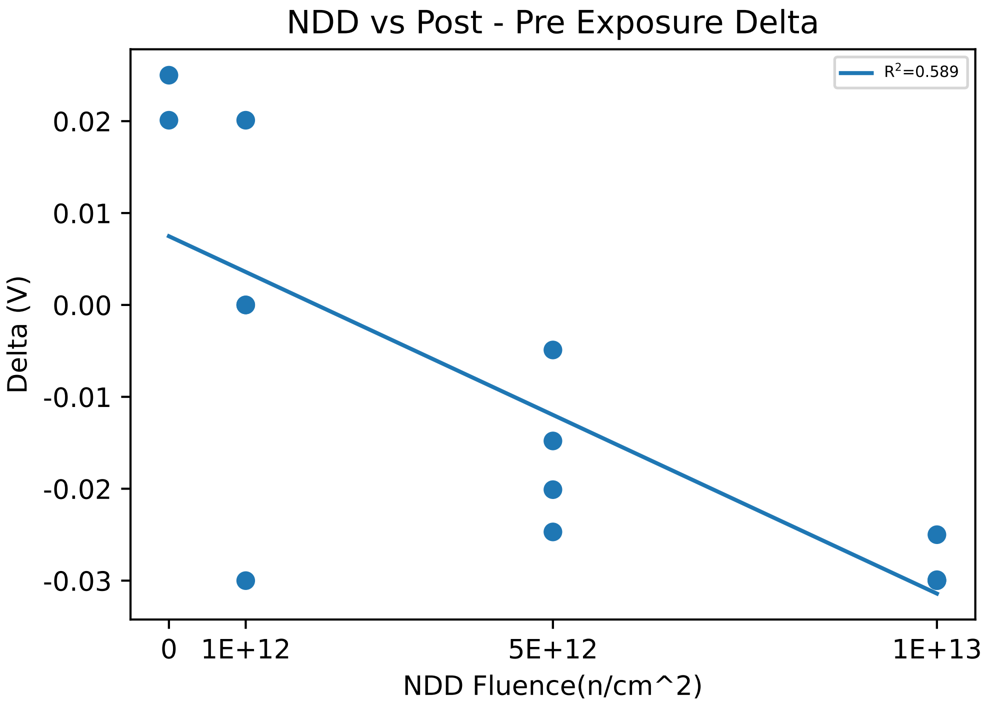
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	4.0599	4.08	0.0201
2	0	Correlation	4.0549	4.08	0.0251
30	1e+12	NDD unbiased	4.08	4.0549	-0.0251
31	1e+12	NDD unbiased	4.0549	4.075	0.0201
32	1e+12	NDD unbiased	4.075	4.075	0
33	1e+12	NDD unbiased	4.0701	4.0651	-0.005
44	5e+12	NDD unbiased	4.0651	4.05	-0.0151
45	5e+12	NDD unbiased	4.0549	4.045	-0.0099
46	5e+12	NDD unbiased	4.0701	4.0549	-0.0152
47	5e+12	NDD unbiased	4.0599	4.045	-0.0149
50	1e+13	NDD unbiased	4.0651	4.0352	-0.0299
51	1e+13	NDD unbiased	4.0651	4.0352	-0.0299
52	1e+13	NDD unbiased	4.0651	4.045	-0.0201
53	1e+13	NDD unbiased	4.0549	4.0249	-0.03

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.0549	4.0574	4.0599	0.0035355	4.08	4.08	4.08	0	0.0201	0.0226	0.0251	0.0035355
1e+12	4.0549	4.07	4.08	0.010848	4.0549	4.0675	4.075	0.0096094	-0.0251	-0.0025	0.0201	0.018565
5e+12	4.0549	4.0625	4.0701	0.0065585	4.045	4.0487	4.0549	0.0047437	-0.0152	-0.013775	-0.0099	0.0025863
1e+13	4.0549	4.0625	4.0651	0.0051	4.0249	4.0351	4.045	0.0082071	-0.03	-0.027475	-0.0201	0.0049169

Device Test: 86.1 V_BP5H_TH_RISE(_UVLO BP5H Rise Thresh VIN_12V)





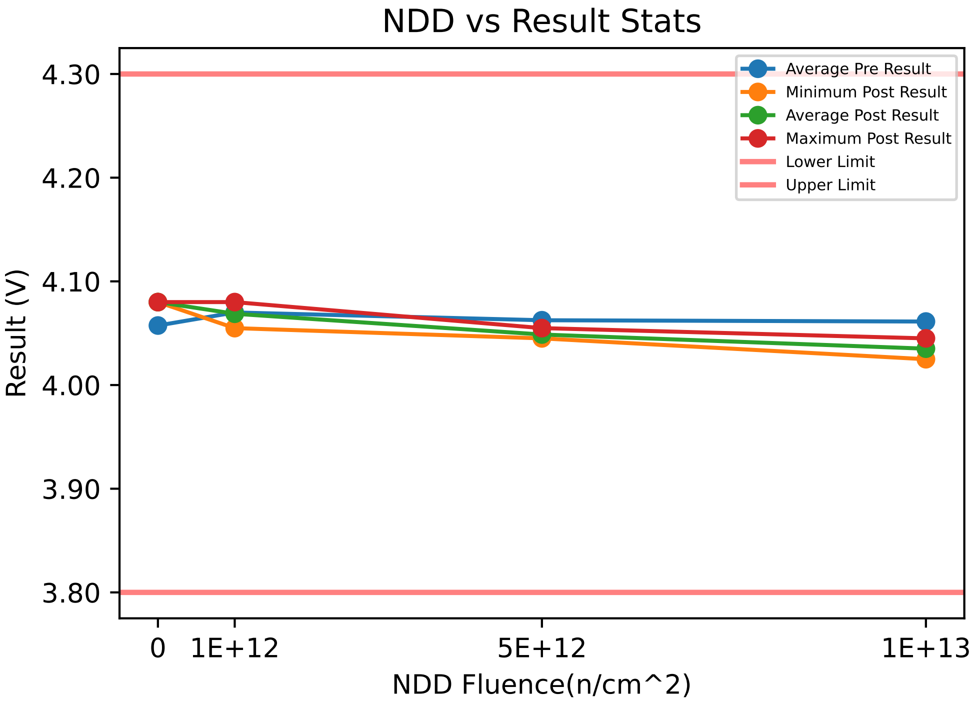
Test Results (Lower Limit = 4.0, Upper Limit = 4.5 (V))

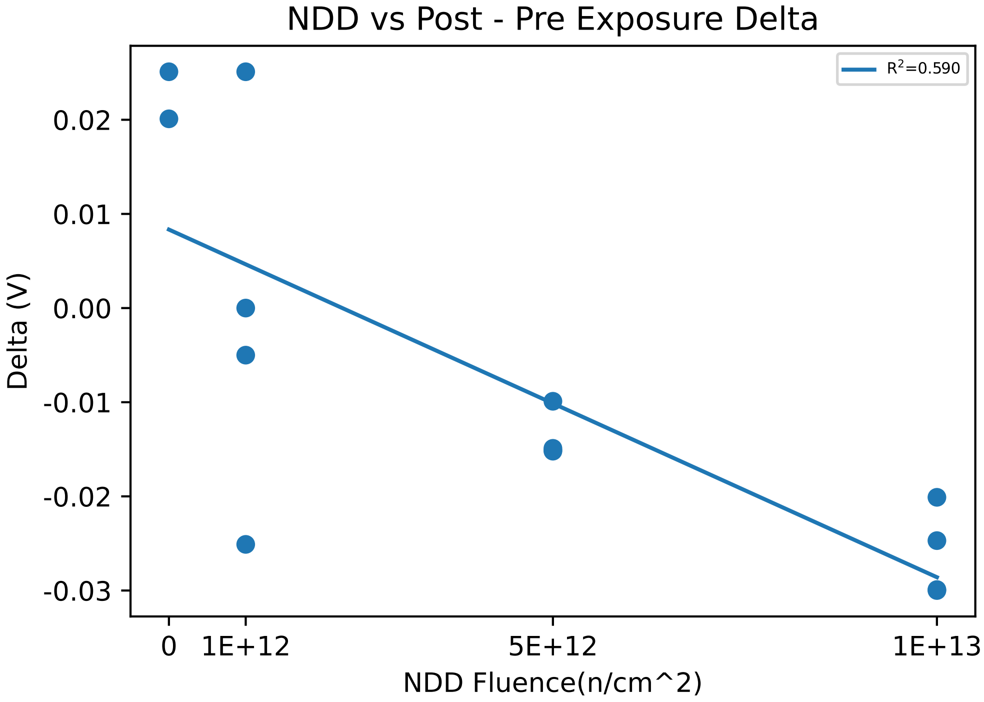
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	4.2599	4.28	0.0201
2	0	Correlation	4.255	4.28	0.025
30	1e+12	NDD unbiased	4.28	4.25	-0.03
31	1e+12	NDD unbiased	4.25	4.2701	0.0201
32	1e+12	NDD unbiased	4.2751	4.2751	0
33	1e+12	NDD unbiased	4.2648	4.2648	0
44	5e+12	NDD unbiased	4.2648	4.2401	-0.0247
45	5e+12	NDD unbiased	4.25	4.2451	-0.0049
46	5e+12	NDD unbiased	4.2701	4.25	-0.0201
47	5e+12	NDD unbiased	4.2599	4.2451	-0.0148
50	1e+13	NDD unbiased	4.2599	4.2299	-0.03
51	1e+13	NDD unbiased	4.2648	4.2349	-0.0299
52	1e+13	NDD unbiased	4.2701	4.2451	-0.025
53	1e+13	NDD unbiased	4.25	4.22	-0.03

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.255	4.2575	4.2599	0.0034648	4.28	4.28	4.28	0	0.0201	0.02255	0.025	0.0034648
1e+12	4.25	4.2675	4.28	0.013261	4.25	4.265	4.2751	0.010848	-0.03	-0.002475	0.0201	0.020652
5e+12	4.25	4.2612	4.2701	0.0085499	4.2401	4.2451	4.25	0.0040418	-0.0247	-0.016125	-0.0049	0.0085066
1e+13	4.25	4.2612	4.2701	0.0085499	4.22	4.2325	4.2451	0.010449	-0.03	-0.028725	-0.025	0.0024838

Device Test: 86.2 V_BP5H_TH_FALL(_UVLO BP5H Fall Thresh VIN_12V)





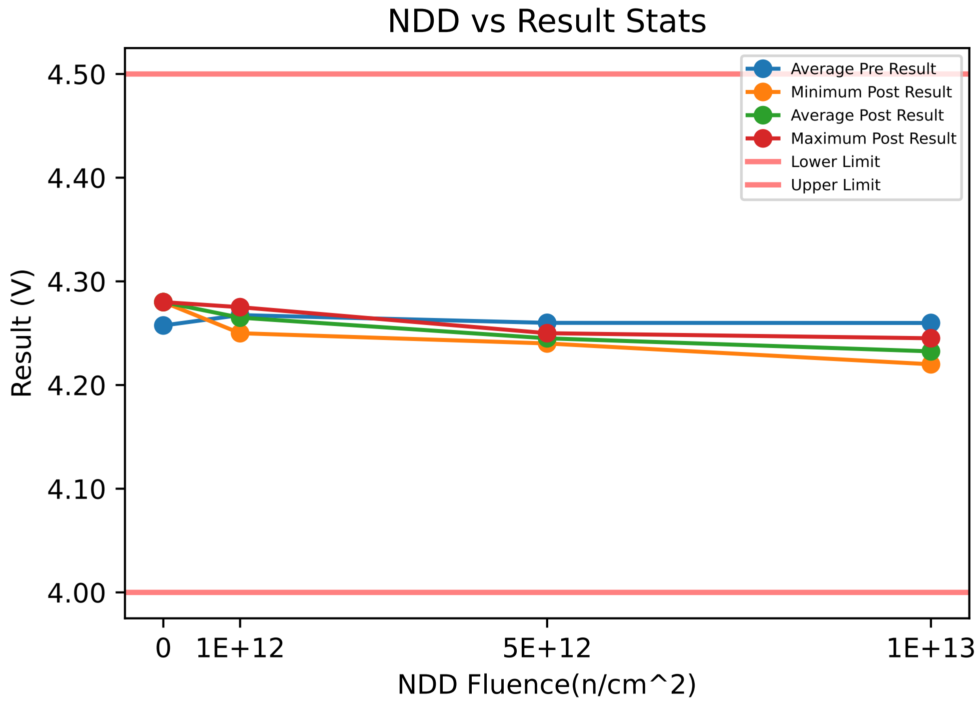
Test Results (Lower Limit = 3.8, Upper Limit = 4.3 (V))

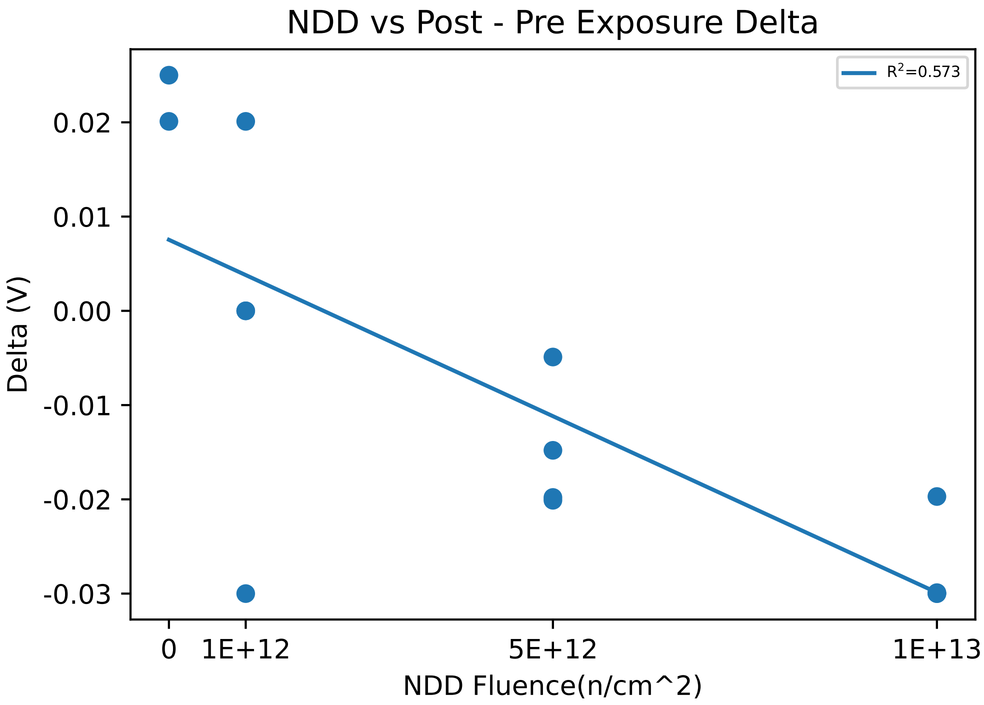
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	4.0599	4.08	0.0201
2	0	Correlation	4.0549	4.08	0.0251
30	1e+12	NDD unbiased	4.08	4.0549	-0.0251
31	1e+12	NDD unbiased	4.0549	4.08	0.0251
32	1e+12	NDD unbiased	4.075	4.075	0
33	1e+12	NDD unbiased	4.0701	4.0651	-0.005
44	5e+12	NDD unbiased	4.0651	4.05	-0.0151
45	5e+12	NDD unbiased	4.0549	4.045	-0.0099
46	5e+12	NDD unbiased	4.0701	4.0549	-0.0152
47	5e+12	NDD unbiased	4.0599	4.045	-0.0149
50	1e+13	NDD unbiased	4.0599	4.0352	-0.0247
51	1e+13	NDD unbiased	4.0651	4.0352	-0.0299
52	1e+13	NDD unbiased	4.0651	4.045	-0.0201
53	1e+13	NDD unbiased	4.0549	4.0249	-0.03

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.0549	4.0574	4.0599	0.0035355	4.08	4.08	4.08	0	0.0201	0.0226	0.0251	0.0035355
1e+12	4.0549	4.07	4.08	0.010848	4.0549	4.0687	4.08	0.011117	-0.0251	-0.00125	0.0251	0.020646
5e+12	4.0549	4.0625	4.0701	0.0065585	4.045	4.0487	4.0549	0.0047437	-0.0152	-0.013775	-0.0099	0.0025863
1e+13	4.0549	4.0613	4.0651	0.0048918	4.0249	4.0351	4.045	0.0082071	-0.03	-0.026175	-0.0201	0.0047465

Device Test: 87.1 V_BP5H_TH_RISE(_UVLO BP5H Rise Thresh VIN_14V)





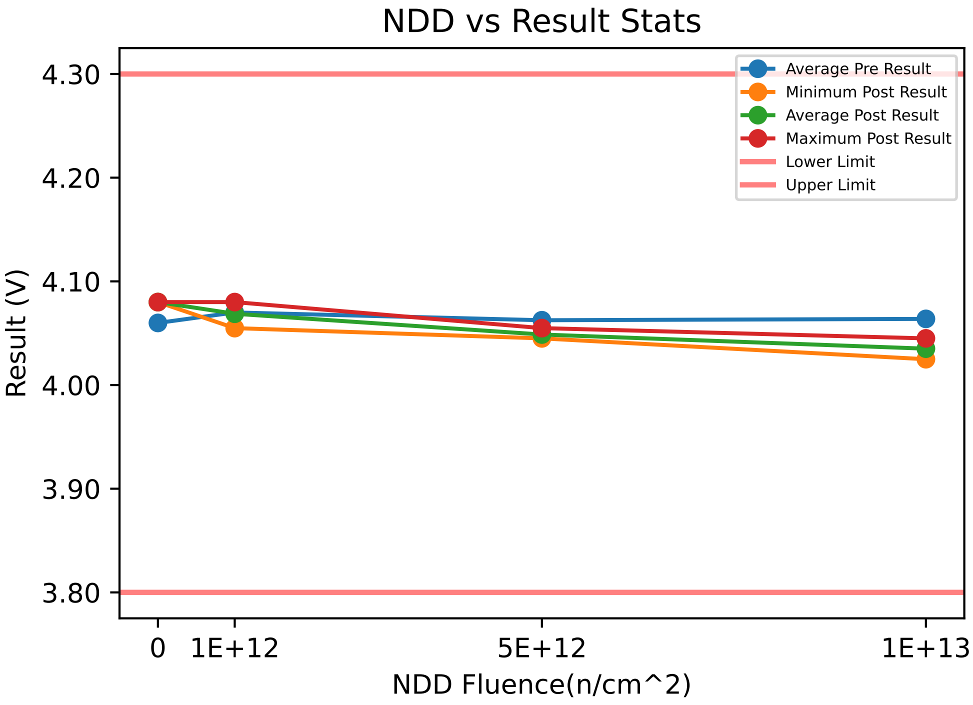
Test Results (Lower Limit = 4.0,
Upper Limit = 4.5 (V))

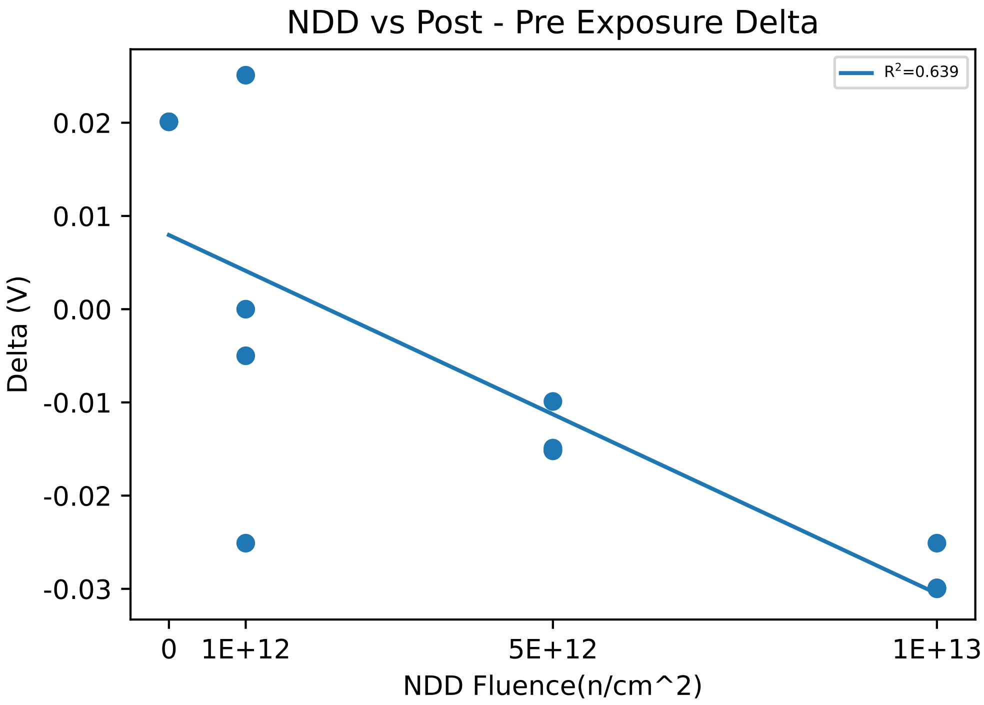
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	4.2599	4.28	0.0201
2	0	Correlation	4.255	4.28	0.025
30	1e+12	NDD unbiased	4.28	4.25	-0.03
31	1e+12	NDD unbiased	4.25	4.2701	0.0201
32	1e+12	NDD unbiased	4.2751	4.2751	0
33	1e+12	NDD unbiased	4.2648	4.2648	0
44	5e+12	NDD unbiased	4.2599	4.2401	-0.0198
45	5e+12	NDD unbiased	4.25	4.2451	-0.0049
46	5e+12	NDD unbiased	4.2701	4.25	-0.0201
47	5e+12	NDD unbiased	4.2599	4.2451	-0.0148
50	1e+13	NDD unbiased	4.2599	4.2299	-0.03
51	1e+13	NDD unbiased	4.2648	4.2349	-0.0299
52	1e+13	NDD unbiased	4.2648	4.2451	-0.0197
53	1e+13	NDD unbiased	4.25	4.22	-0.03

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.255	4.2575	4.2599	0.0034648	4.28	4.28	4.28	0	0.0201	0.02255	0.025	0.0034648
1e+12	4.25	4.2675	4.28	0.013261	4.25	4.265	4.2751	0.010848	-0.03	-0.002475	0.0201	0.020652
5e+12	4.25	4.26	4.2701	0.0082062	4.2401	4.2451	4.25	0.0040418	-0.0201	-0.0149	-0.0049	0.007096
1e+13	4.25	4.2599	4.2648	0.0069768	4.22	4.2325	4.2451	0.010449	-0.03	-0.0274	-0.0197	0.0051335

Device Test: 87.2 V_BP5H_TH_FALL(_UVLO BP5H Fall Thresh VIN_14V)


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

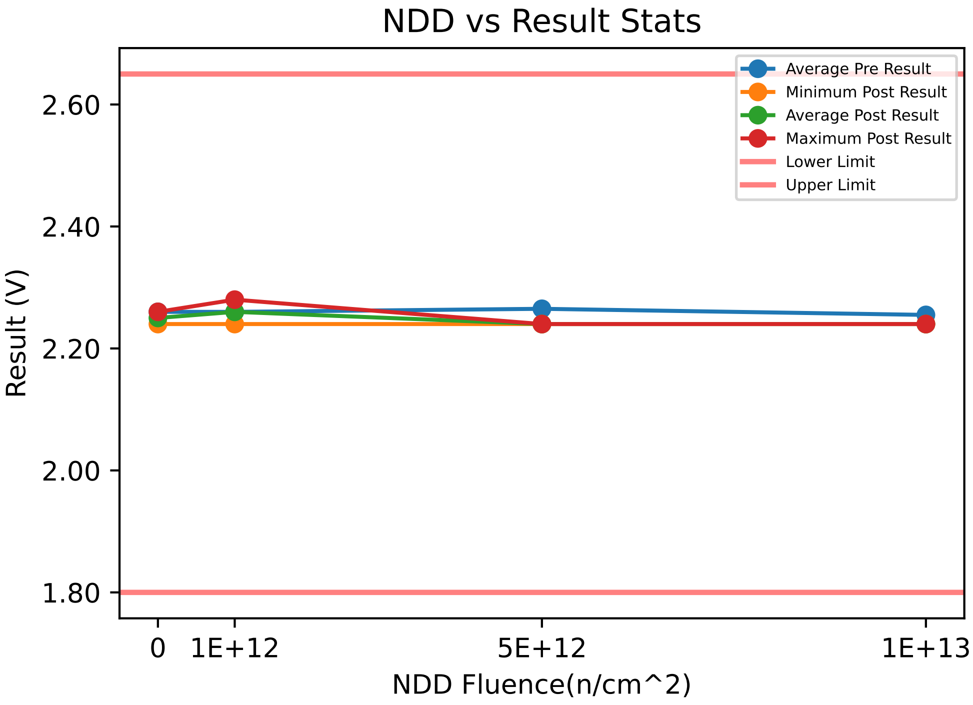
Test Results (Lower Limit = 3.8, Upper Limit = 4.3 (V))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	4.0599	4.08	0.0201
2	0	Correlation	4.0599	4.08	0.0201
30	1e+12	NDD unbiased	4.08	4.0549	-0.0251
31	1e+12	NDD unbiased	4.0549	4.08	0.0251
32	1e+12	NDD unbiased	4.075	4.075	0
33	1e+12	NDD unbiased	4.0701	4.0651	-0.005
44	5e+12	NDD unbiased	4.0651	4.05	-0.0151
45	5e+12	NDD unbiased	4.0549	4.045	-0.0099
46	5e+12	NDD unbiased	4.0701	4.0549	-0.0152
47	5e+12	NDD unbiased	4.0599	4.045	-0.0149
50	1e+13	NDD unbiased	4.0651	4.0352	-0.0299
51	1e+13	NDD unbiased	4.0651	4.0352	-0.0299
52	1e+13	NDD unbiased	4.0701	4.045	-0.0251
53	1e+13	NDD unbiased	4.0549	4.0249	-0.03

Test Statistics (V)

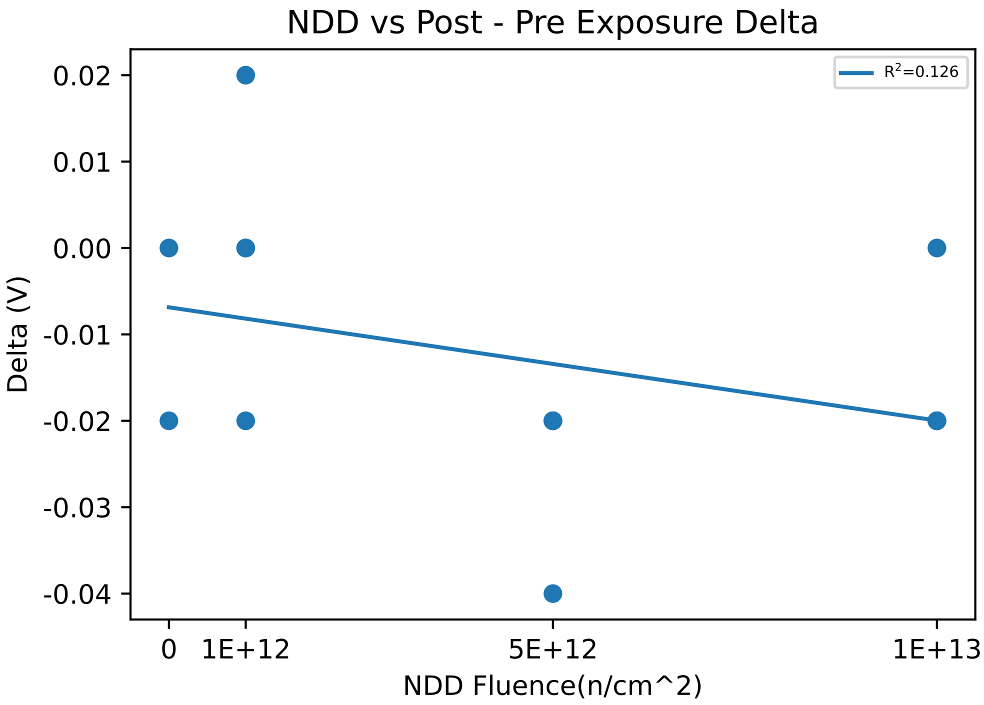
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.0599	4.0599	4.0599	0	4.08	4.08	4.08	0	0.0201	0.0201	0.0201	0
1e+12	4.0549	4.07	4.08	0.010848	4.0549	4.0687	4.08	0.011117	-0.0251	-0.00125	0.0251	0.020646
5e+12	4.0549	4.0625	4.0701	0.0065585	4.045	4.0487	4.0549	0.0047437	-0.0152	-0.013775	-0.0099	0.0025863
1e+13	4.0549	4.0638	4.0701	0.0063844	4.0249	4.0351	4.045	0.0082071	-0.03	-0.028725	-0.0251	0.0024171

Device Test: 90.0 V_IH(_PWM_LI Rise Thresh VIN_10V)


NDD vs Result Stats

Test Results (Lower Limit = 1.8, Upper Limit = 2.65 (V))

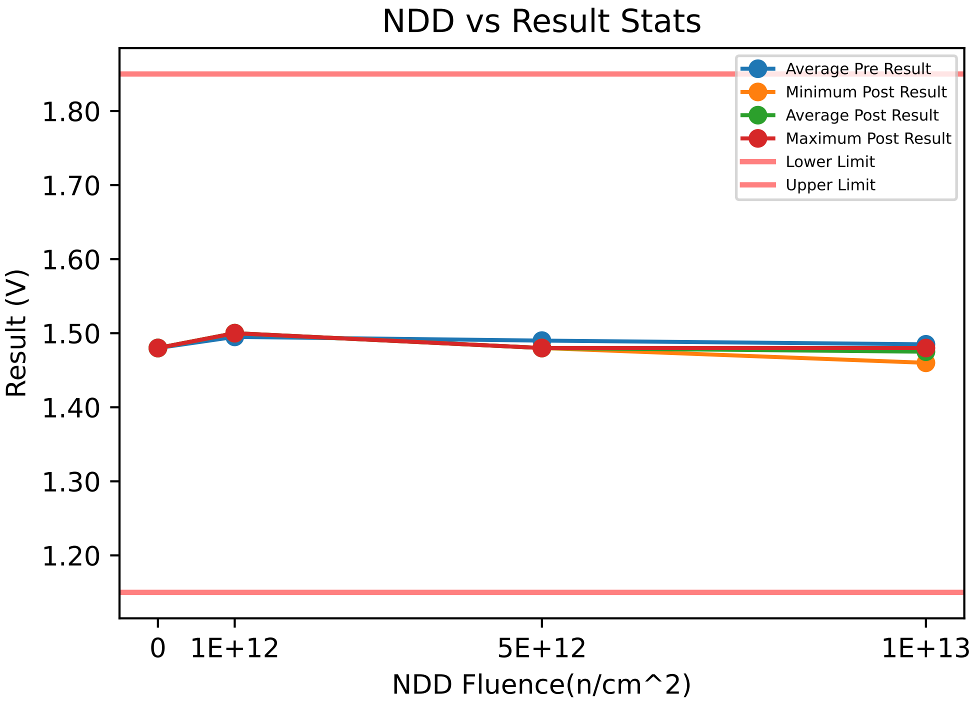
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	2.26	2.24	-0.02
2	0	Correlation	2.26	2.26	0
30	1e+12	NDD unbiased	2.28	2.26	-0.02
31	1e+12	NDD unbiased	2.26	2.28	0.02
32	1e+12	NDD unbiased	2.24	2.24	0
33	1e+12	NDD unbiased	2.26	2.26	0
44	5e+12	NDD unbiased	2.26	2.24	-0.02
45	5e+12	NDD unbiased	2.28	2.24	-0.04
46	5e+12	NDD unbiased	2.26	2.24	-0.02
47	5e+12	NDD unbiased	2.26	2.24	-0.02
50	1e+13	NDD unbiased	2.26	2.24	-0.02
51	1e+13	NDD unbiased	2.24	2.24	0
52	1e+13	NDD unbiased	2.26	2.24	-0.02
53	1e+13	NDD unbiased	2.26	2.24	-0.02

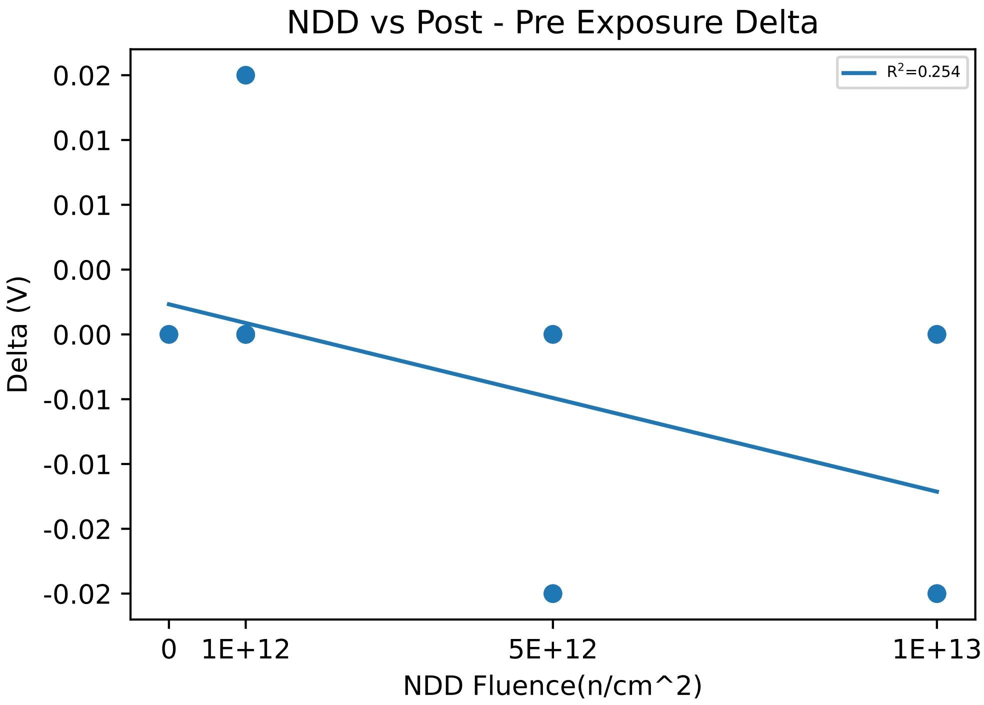

NDD vs Post - Pre Exposure Delta

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.26	2.26	2.26	0	2.24	2.25	2.26	0.014142	-0.02	-0.01	0	0.014142
1e+12	2.24	2.26	2.28	0.01633	2.24	2.26	2.28	0.01633	-0.02	0	0.02	0.01633
5e+12	2.26	2.265	2.28	0.01	2.24	2.24	2.24	0	-0.04	-0.025	-0.02	0.01
1e+13	2.24	2.255	2.26	0.01	2.24	2.24	2.24	0	-0.02	-0.015	0	0.01

Device Test: 90.1 V_IL(_PWM_LI Fall Thresh VIN_10V)





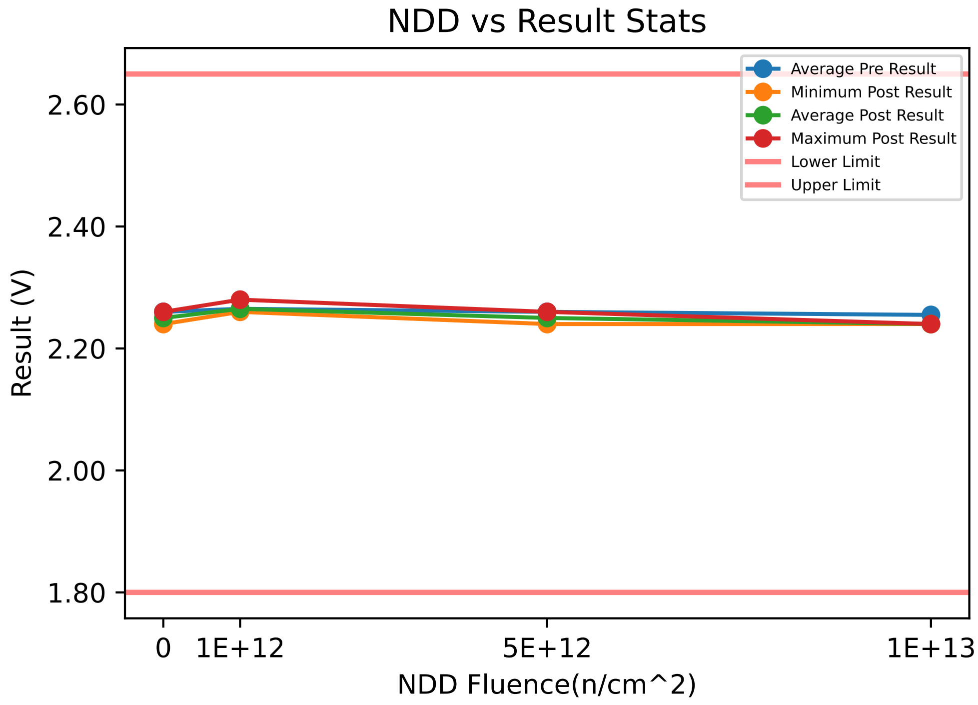
Test Results (Lower Limit = 1.15, Upper Limit = 1.85 (V))

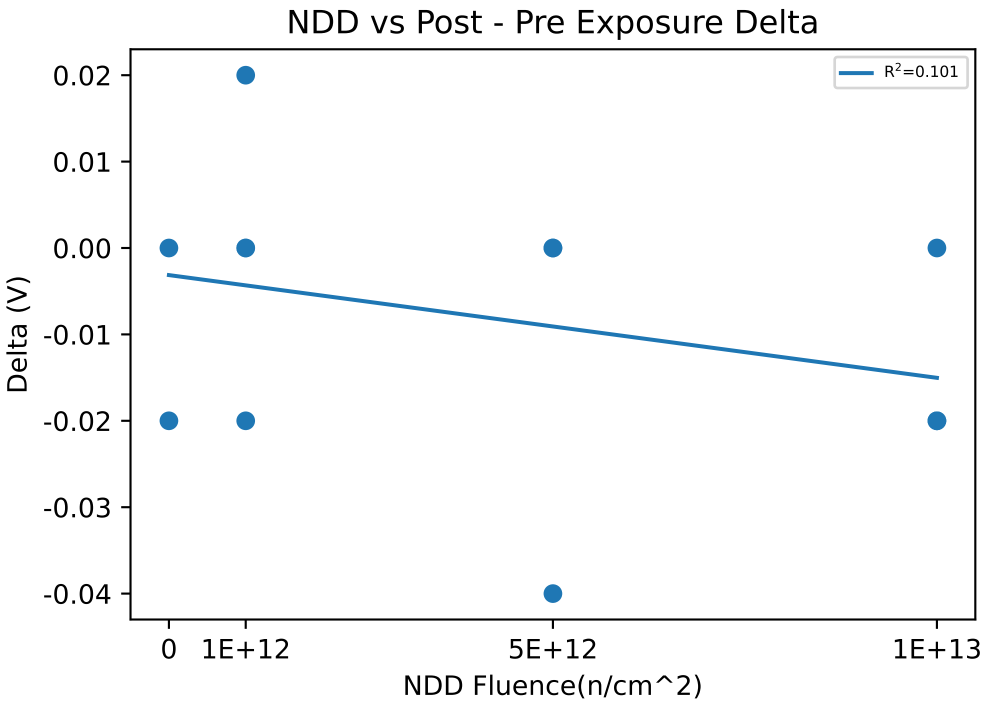
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	1.48	1.48	0
2	0	Correlation	1.48	1.48	0
30	1e+12	NDD unbiased	1.5	1.5	0
31	1e+12	NDD unbiased	1.5	1.5	0
32	1e+12	NDD unbiased	1.48	1.5	0.02
33	1e+12	NDD unbiased	1.5	1.5	0
44	5e+12	NDD unbiased	1.48	1.48	0
45	5e+12	NDD unbiased	1.5	1.48	-0.02
46	5e+12	NDD unbiased	1.5	1.48	-0.02
47	5e+12	NDD unbiased	1.48	1.48	0
50	1e+13	NDD unbiased	1.48	1.48	0
51	1e+13	NDD unbiased	1.48	1.46	-0.02
52	1e+13	NDD unbiased	1.5	1.48	-0.02
53	1e+13	NDD unbiased	1.48	1.48	0

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.48	1.48	1.48	0	1.48	1.48	1.48	0	0	0	0	0
1e+12	1.48	1.495	1.5	0.01	1.5	1.5	1.5	0	0	0.005	0.02	0.01
5e+12	1.48	1.49	1.5	0.011547	1.48	1.48	1.48	0	-0.02	-0.01	0	0.011547
1e+13	1.48	1.485	1.5	0.01	1.46	1.475	1.48	0.01	-0.02	-0.01	0	0.011547

Device Test: 90.3 V_IH(_EN_HI Rise Thresh VIN_10V)


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

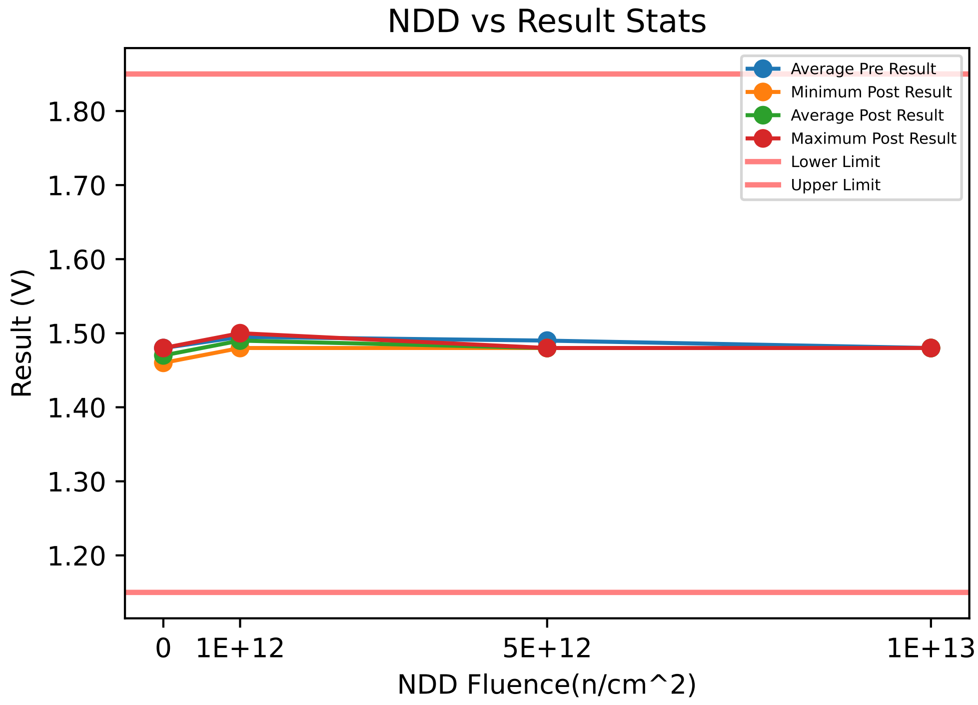
Test Results (Lower Limit = 1.8, Upper Limit = 2.65 (V))

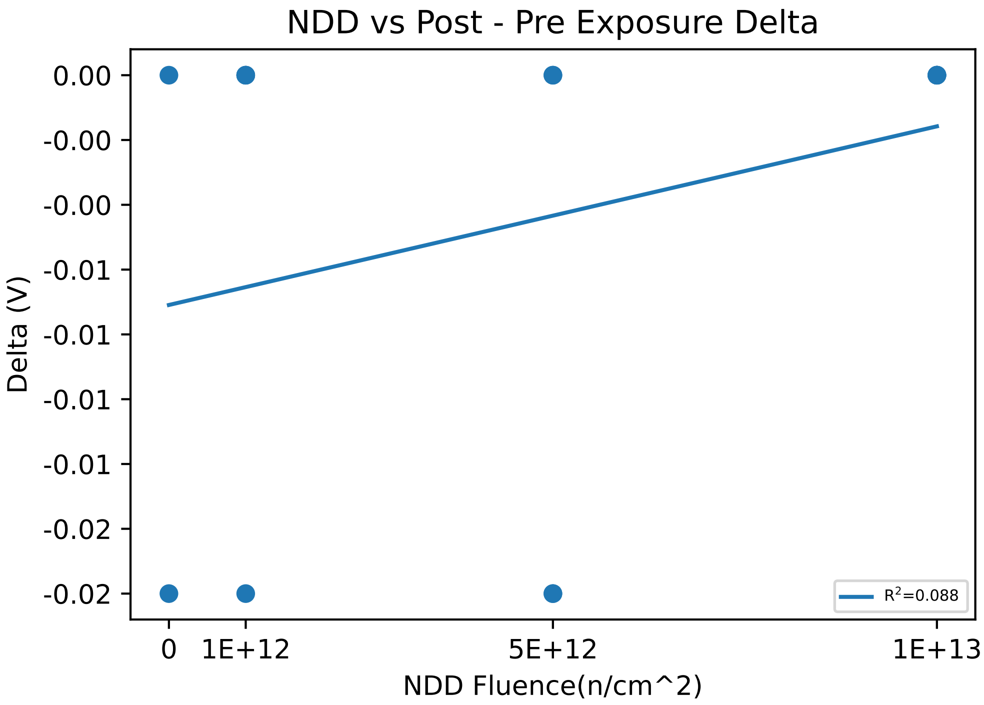
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	2.26	2.24	-0.02
2	0	Correlation	2.26	2.26	0
30	1e+12	NDD unbiased	2.28	2.26	-0.02
31	1e+12	NDD unbiased	2.26	2.28	0.02
32	1e+12	NDD unbiased	2.26	2.26	0
33	1e+12	NDD unbiased	2.26	2.26	0
44	5e+12	NDD unbiased	2.26	2.26	0
45	5e+12	NDD unbiased	2.28	2.24	-0.04
46	5e+12	NDD unbiased	2.26	2.26	0
47	5e+12	NDD unbiased	2.24	2.24	0
50	1e+13	NDD unbiased	2.26	2.24	-0.02
51	1e+13	NDD unbiased	2.24	2.24	0
52	1e+13	NDD unbiased	2.26	2.24	-0.02
53	1e+13	NDD unbiased	2.26	2.24	-0.02

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.26	2.26	2.26	0	2.24	2.25	2.26	0.014142	-0.02	-0.01	0	0.014142
1e+12	2.26	2.265	2.28	0.01	2.26	2.265	2.28	0.01	-0.02	0	0.02	0.01633
5e+12	2.24	2.26	2.28	0.01633	2.24	2.25	2.26	0.011547	-0.04	-0.01	0	0.02
1e+13	2.24	2.255	2.26	0.01	2.24	2.24	2.24	0	-0.02	-0.015	0	0.01

Device Test: 90.4 V_IL(_EN_HI Fall Thresh VIN_10V)





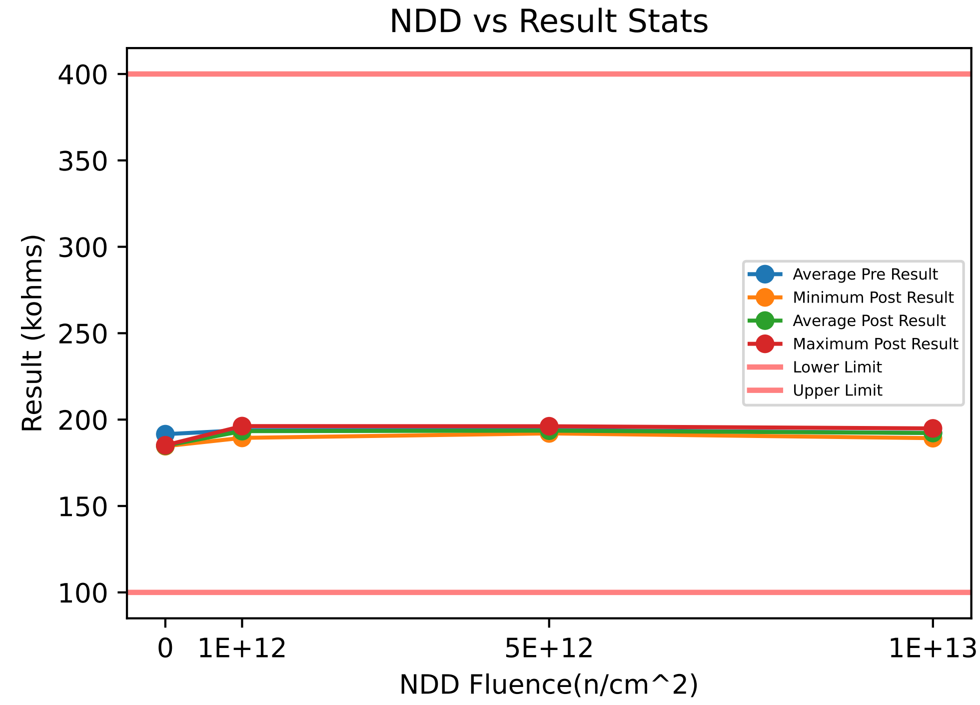
Test Results (Lower Limit = 1.15, Upper Limit = 1.85 (V))

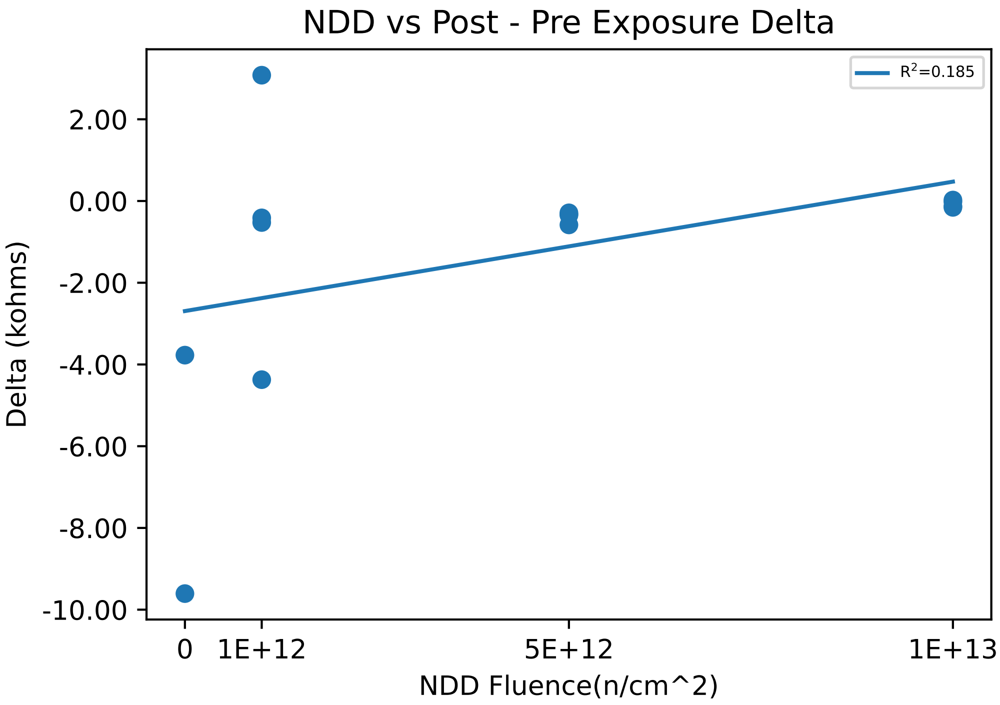
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	1.48	1.46	-0.02
2	0	Correlation	1.48	1.48	0
30	1e+12	NDD unbiased	1.5	1.5	0
31	1e+12	NDD unbiased	1.5	1.5	0
32	1e+12	NDD unbiased	1.48	1.48	0
33	1e+12	NDD unbiased	1.5	1.48	-0.02
44	5e+12	NDD unbiased	1.48	1.48	0
45	5e+12	NDD unbiased	1.5	1.48	-0.02
46	5e+12	NDD unbiased	1.5	1.48	-0.02
47	5e+12	NDD unbiased	1.48	1.48	0
50	1e+13	NDD unbiased	1.48	1.48	0
51	1e+13	NDD unbiased	1.48	1.48	0
52	1e+13	NDD unbiased	1.48	1.48	0
53	1e+13	NDD unbiased	1.48	1.48	0

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.48	1.48	1.48	0	1.46	1.47	1.48	0.014142	-0.02	-0.01	0	0.014142
1e+12	1.48	1.495	1.5	0.01	1.48	1.49	1.5	0.011547	-0.02	-0.005	0	0.01
5e+12	1.48	1.49	1.5	0.011547	1.48	1.48	1.48	0	-0.02	-0.01	0	0.011547
1e+13	1.48	1.48	1.48	0	1.48	1.48	1.48	0	0	0	0	0

Device Test: 90.6 R_PD(_PWM_LI Pull Down Resistance VIN_10V)


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

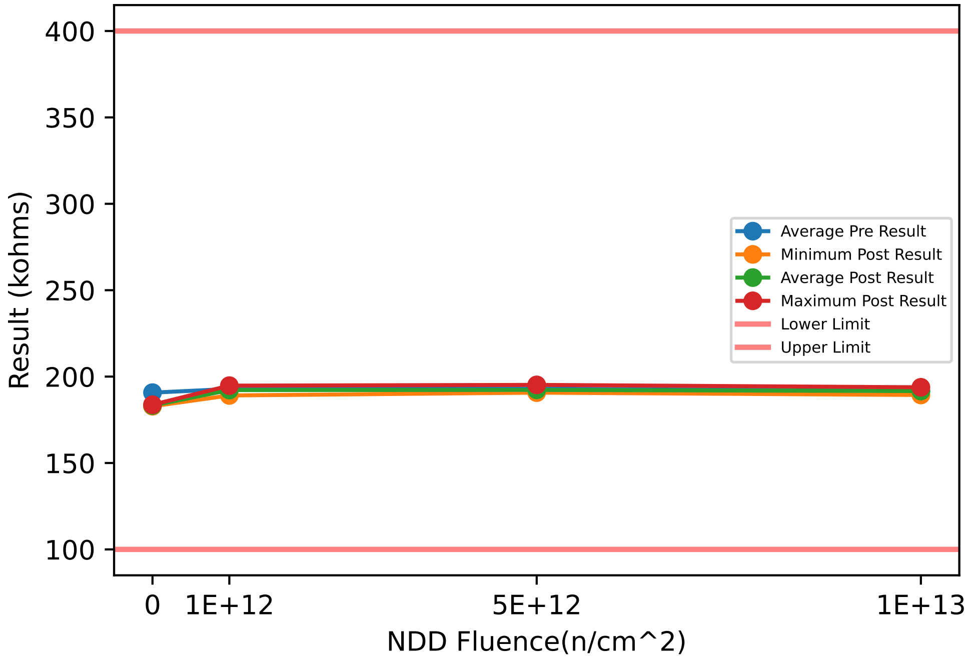
Test Results (Lower Limit = 100.0, Upper Limit = 400.0 (kohms))

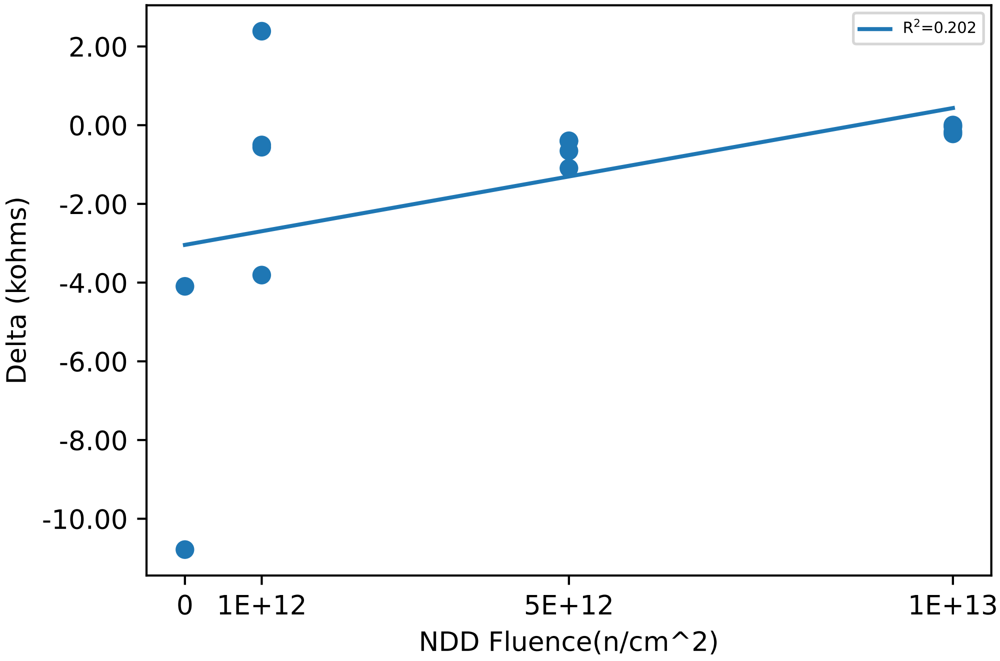
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	194.21	184.61	-9.6067
2	0	Correlation	188.91	185.14	-3.7716
30	1e+12	NDD unbiased	196.27	191.9	-4.3718
31	1e+12	NDD unbiased	192.62	195.7	3.0785
32	1e+12	NDD unbiased	189.83	189.42	-0.4129
33	1e+12	NDD unbiased	196.76	196.23	-0.5261
44	5e+12	NDD unbiased	194.65	194.07	-0.5845
45	5e+12	NDD unbiased	192.43	192.14	-0.2895
46	5e+12	NDD unbiased	196.5	196.15	-0.3448
47	5e+12	NDD unbiased	192.34	192.01	-0.3276
50	1e+13	NDD unbiased	193.5	193.52	0.0236
51	1e+13	NDD unbiased	191.37	191.21	-0.1556
52	1e+13	NDD unbiased	194.92	194.9	-0.0206
53	1e+13	NDD unbiased	189.38	189.25	-0.1269

Test Statistics (kohms)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	188.91	191.56	194.21	3.7524	184.61	184.87	185.14	0.37364	-9.6067	-6.6891	-3.7716	4.126
1e+12	189.83	193.87	196.76	3.265	189.42	193.31	196.23	3.2353	-4.3718	-0.55808	3.0785	3.0436
5e+12	192.34	193.98	196.5	1.9909	192.01	193.59	196.15	1.9488	-0.5845	-0.3866	-0.2895	0.13394
1e+13	189.38	192.29	194.92	2.4306	189.25	192.22	194.9	2.4981	-0.1556	-0.069875	0.0236	0.085179

Device Test: 90.7 R_PD(_EN_HI Pull Down Resistance VIN_10V)


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

Test Results (Lower Limit = 100.0, Upper Limit = 400.0 (kohms))

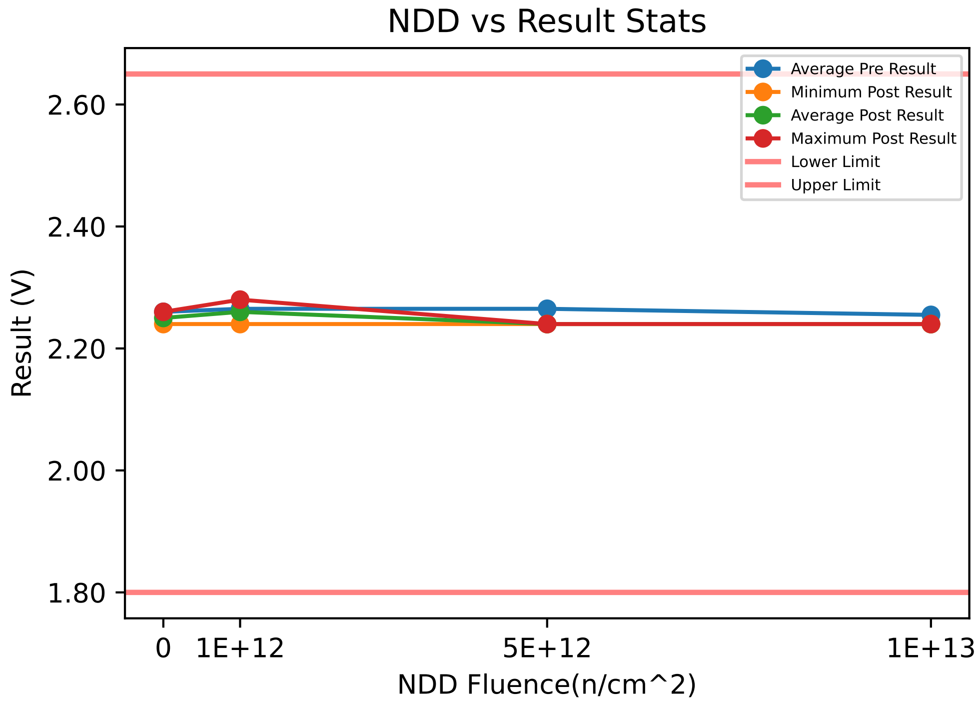
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	193.63	182.85	-10.784
2	0	Correlation	187.8	183.71	-4.0953
30	1e+12	NDD unbiased	194.7	190.89	-3.8089
31	1e+12	NDD unbiased	191.67	194.06	2.3876
32	1e+12	NDD unbiased	189.6	189.1	-0.5027
33	1e+12	NDD unbiased	195.33	194.77	-0.5603
44	5e+12	NDD unbiased	193.13	192.48	-0.6542
45	5e+12	NDD unbiased	191.92	190.83	-1.0935
46	5e+12	NDD unbiased	195.6	195.2	-0.3968
47	5e+12	NDD unbiased	191.12	190.71	-0.4057
50	1e+13	NDD unbiased	193.44	193.45	0.004
51	1e+13	NDD unbiased	190.11	189.89	-0.2215
52	1e+13	NDD unbiased	193.85	193.81	-0.0418
53	1e+13	NDD unbiased	189.53	189.37	-0.1627

Test Statistics (kohms)

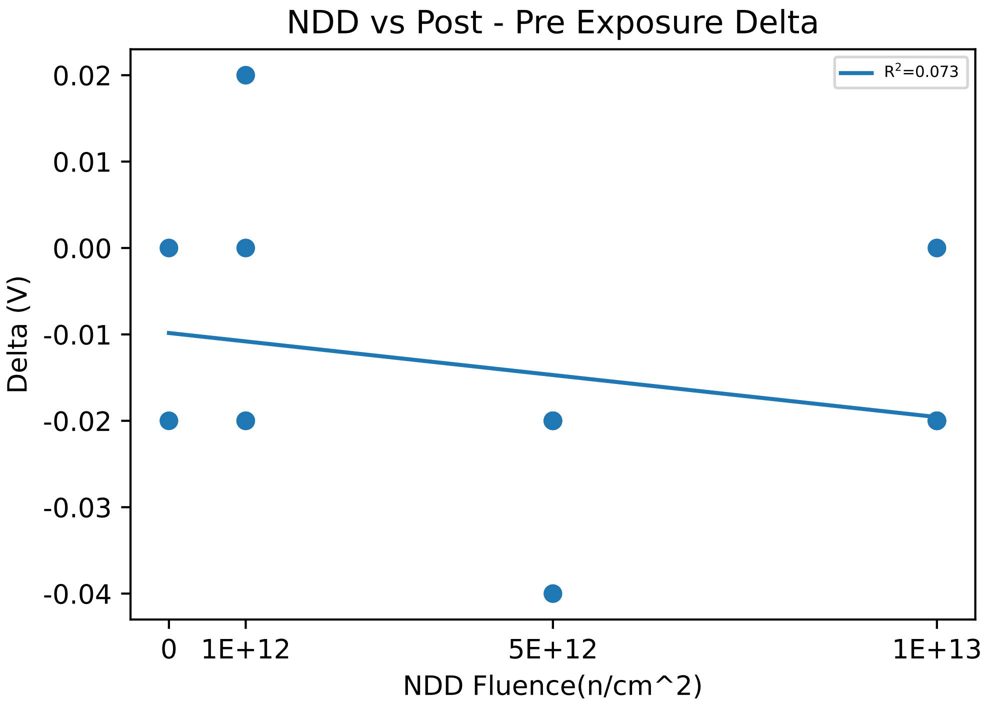
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	187.8	190.72	193.63	4.1197	182.85	183.28	183.71	0.60974	-10.784	-7.4395	-4.0953	4.7295
1e+12	189.6	192.83	195.33	2.6789	189.1	192.2	194.77	2.6697	-3.8089	-0.62108	2.3876	2.5319
5e+12	191.12	192.94	195.6	1.9528	190.71	192.31	195.2	2.0909	-1.0935	-0.63755	-0.3968	0.32654
1e+13	189.53	191.74	193.85	2.2292	189.37	191.63	193.81	2.3248	-0.2215	-0.1055	0.004	0.10452

Device Test: 91.0 V_IH(_PWM_LI Rise Thresh VIN_12V)

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



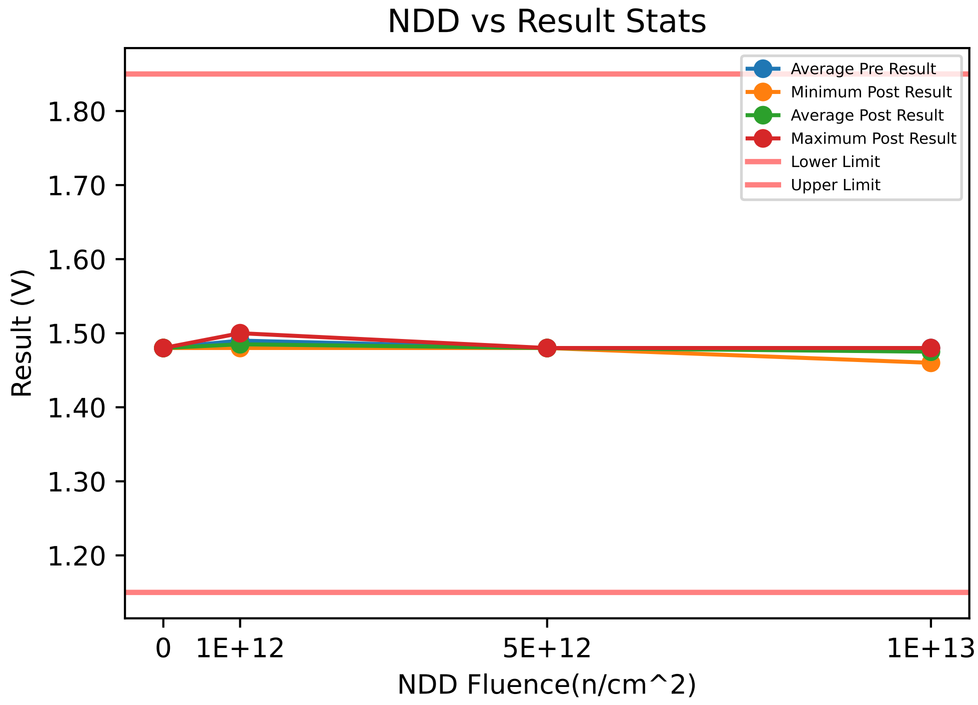
Test Results (Lower Limit = 1.8, Upper Limit = 2.65 (V))

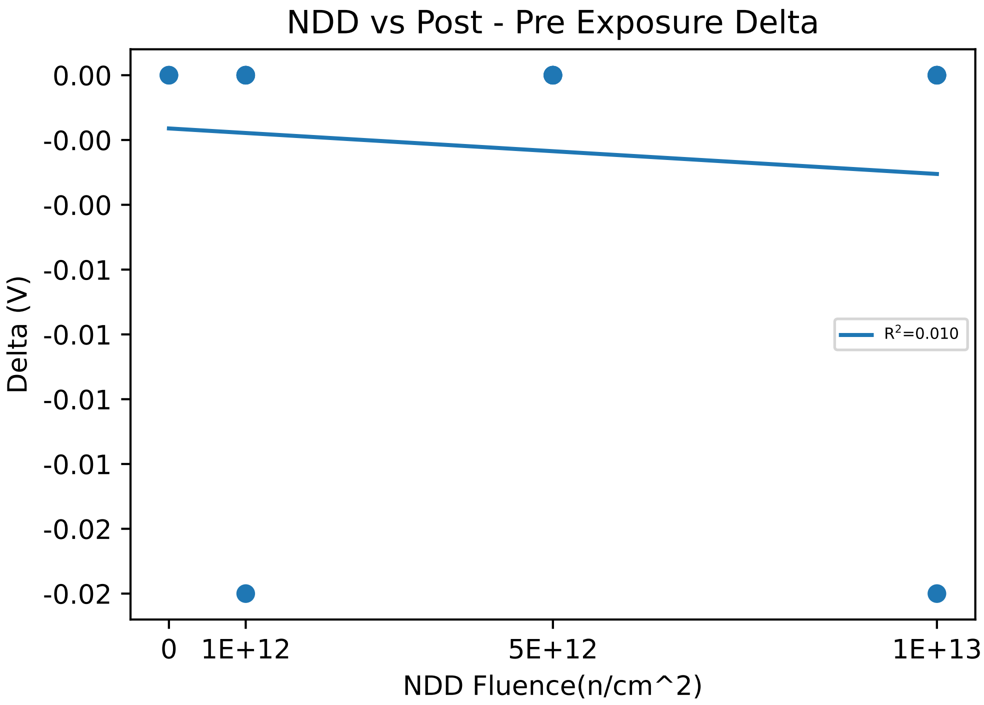
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	2.26	2.24	-0.02
2	0	Correlation	2.26	2.26	0
30	1e+12	NDD unbiased	2.28	2.26	-0.02
31	1e+12	NDD unbiased	2.26	2.28	0.02
32	1e+12	NDD unbiased	2.26	2.24	-0.02
33	1e+12	NDD unbiased	2.26	2.26	0
44	5e+12	NDD unbiased	2.26	2.24	-0.02
45	5e+12	NDD unbiased	2.28	2.24	-0.04
46	5e+12	NDD unbiased	2.26	2.24	-0.02
47	5e+12	NDD unbiased	2.26	2.24	-0.02
50	1e+13	NDD unbiased	2.26	2.24	-0.02
51	1e+13	NDD unbiased	2.26	2.24	-0.02
52	1e+13	NDD unbiased	2.26	2.24	-0.02
53	1e+13	NDD unbiased	2.24	2.24	0

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.26	2.26	2.26	0	2.24	2.25	2.26	0.014142	-0.02	-0.01	0	0.014142
1e+12	2.26	2.265	2.28	0.01	2.24	2.26	2.28	0.01633	-0.02	-0.005	0.02	0.019149
5e+12	2.26	2.265	2.28	0.01	2.24	2.24	2.24	0	-0.04	-0.025	-0.02	0.01
1e+13	2.24	2.255	2.26	0.01	2.24	2.24	2.24	0	-0.02	-0.015	0	0.01

Device Test: 91.1 V_IL(_PWM_LI Fall Thresh VIN_12V)





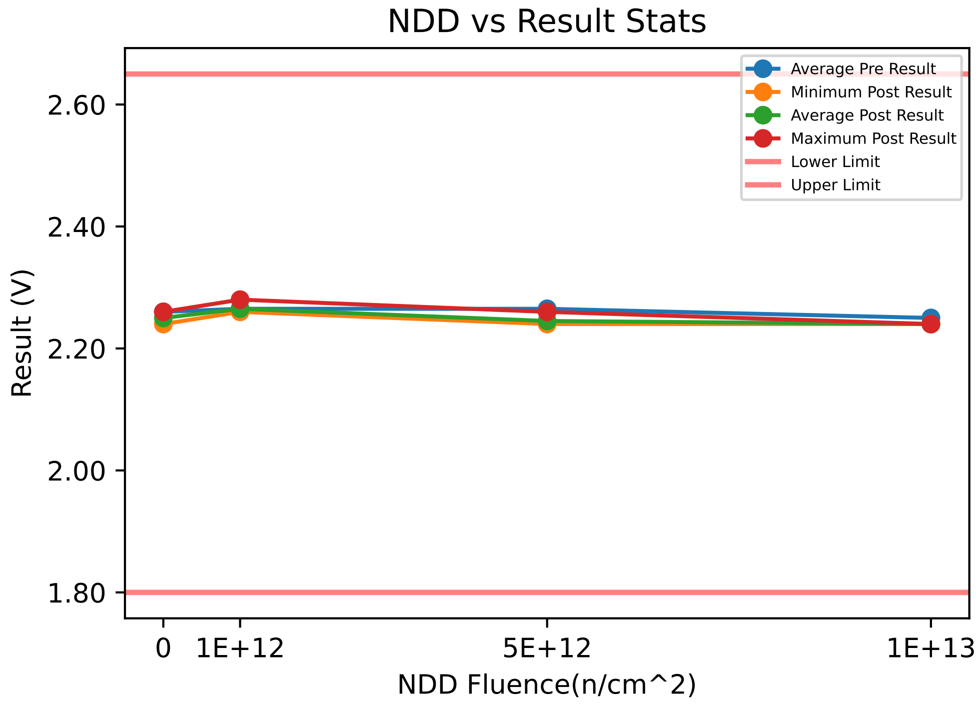
Test Results (Lower Limit = 1.15, Upper Limit = 1.85 (V))

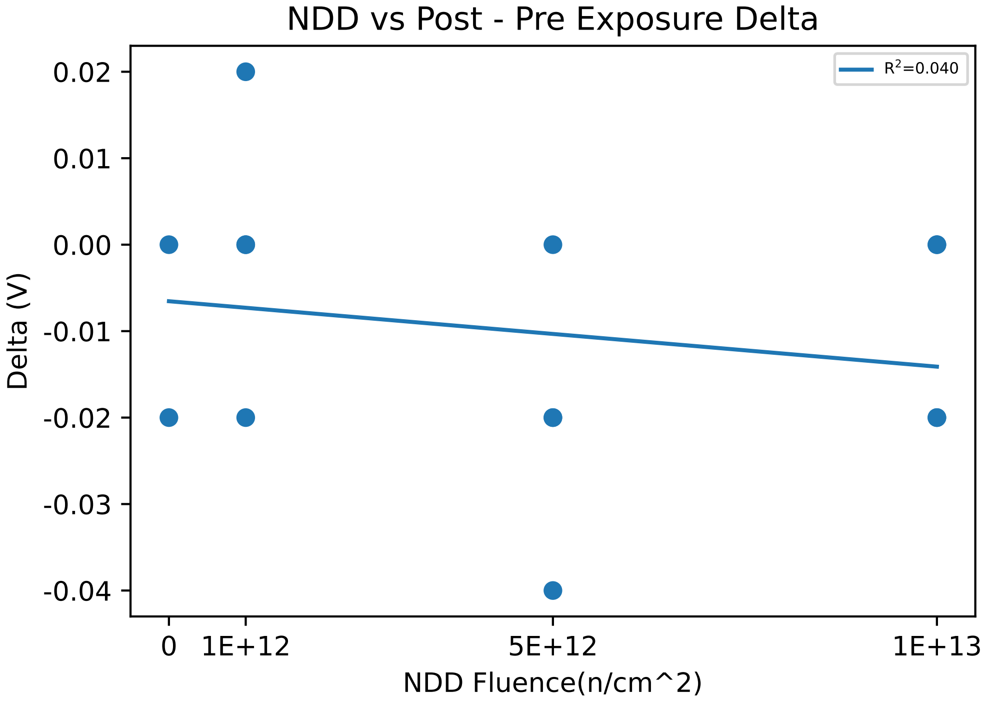
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	1.48	1.48	0
2	0	Correlation	1.48	1.48	0
30	1e+12	NDD unbiased	1.5	1.48	-0.02
31	1e+12	NDD unbiased	1.5	1.5	0
32	1e+12	NDD unbiased	1.48	1.48	0
33	1e+12	NDD unbiased	1.48	1.48	0
44	5e+12	NDD unbiased	1.48	1.48	0
45	5e+12	NDD unbiased	1.48	1.48	0
46	5e+12	NDD unbiased	1.48	1.48	0
47	5e+12	NDD unbiased	1.48	1.48	0
50	1e+13	NDD unbiased	1.48	1.48	0
51	1e+13	NDD unbiased	1.48	1.46	-0.02
52	1e+13	NDD unbiased	1.48	1.48	0
53	1e+13	NDD unbiased	1.48	1.48	0

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.48	1.48	1.48	0	1.48	1.48	1.48	0	0	0	0	0
1e+12	1.48	1.49	1.5	0.011547	1.48	1.485	1.5	0.01	-0.02	-0.005	0	0.01
5e+12	1.48	1.48	1.48	0	1.48	1.48	1.48	0	0	0	0	0
1e+13	1.48	1.48	1.48	0	1.46	1.475	1.48	0.01	-0.02	-0.005	0	0.01

Device Test: 91.3 V_IH(_EN_HI Rise Thresh VIN_12V)





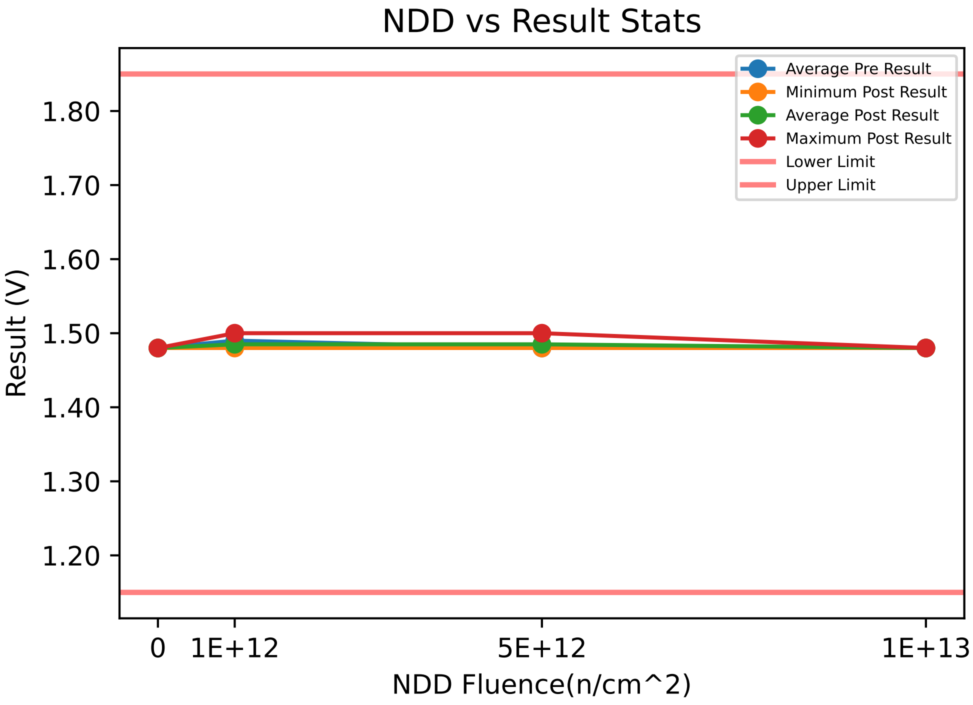
Test Results (Lower Limit = 1.8, Upper Limit = 2.65 (V))

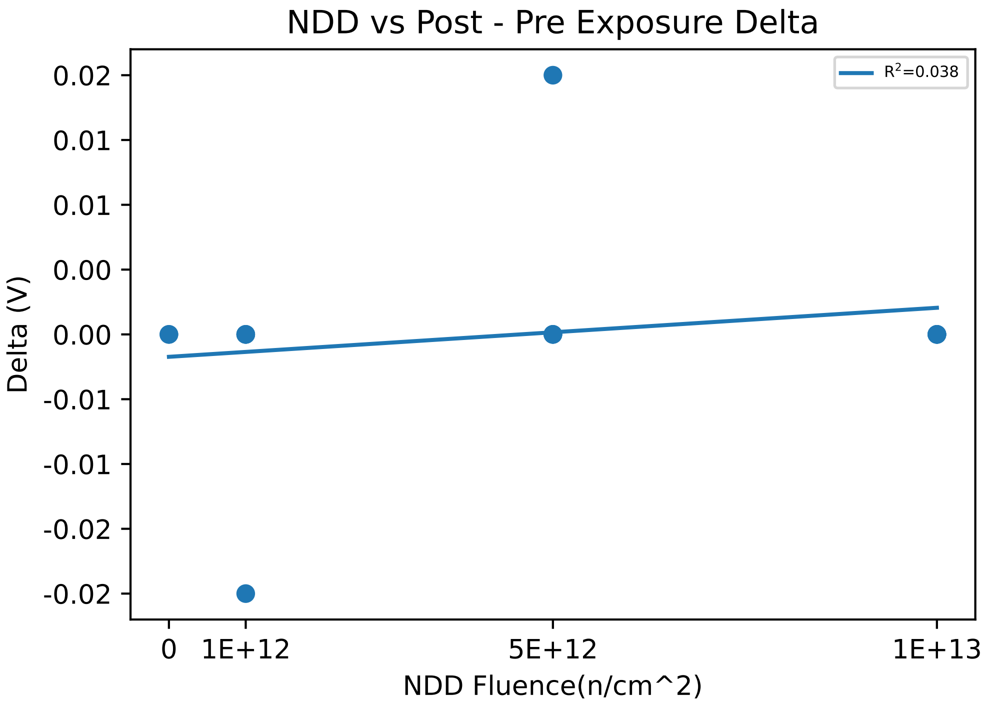
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	2.26	2.24	-0.02
2	0	Correlation	2.26	2.26	0
30	1e+12	NDD unbiased	2.28	2.26	-0.02
31	1e+12	NDD unbiased	2.26	2.28	0.02
32	1e+12	NDD unbiased	2.26	2.26	0
33	1e+12	NDD unbiased	2.26	2.26	0
44	5e+12	NDD unbiased	2.26	2.24	-0.02
45	5e+12	NDD unbiased	2.28	2.24	-0.04
46	5e+12	NDD unbiased	2.26	2.26	0
47	5e+12	NDD unbiased	2.26	2.24	-0.02
50	1e+13	NDD unbiased	2.26	2.24	-0.02
51	1e+13	NDD unbiased	2.24	2.24	0
52	1e+13	NDD unbiased	2.26	2.24	-0.02
53	1e+13	NDD unbiased	2.24	2.24	0

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.26	2.26	2.26	0	2.24	2.25	2.26	0.014142	-0.02	-0.01	0	0.014142
1e+12	2.26	2.265	2.28	0.01	2.26	2.265	2.28	0.01	-0.02	0	0.02	0.01633
5e+12	2.26	2.265	2.28	0.01	2.24	2.245	2.26	0.01	-0.04	-0.02	0	0.01633
1e+13	2.24	2.25	2.26	0.011547	2.24	2.24	2.24	0	-0.02	-0.01	0	0.011547

Device Test: 91.4 V_IL(_EN_HI Fall Thresh VIN_12V)





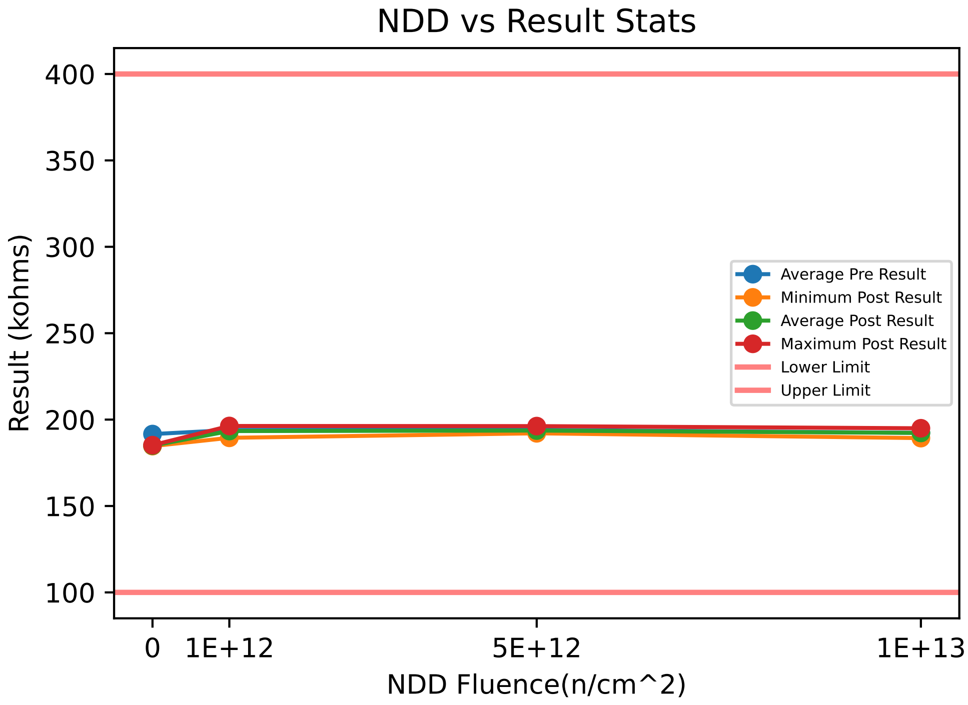
Test Results (Lower Limit = 1.15, Upper Limit = 1.85 (V))

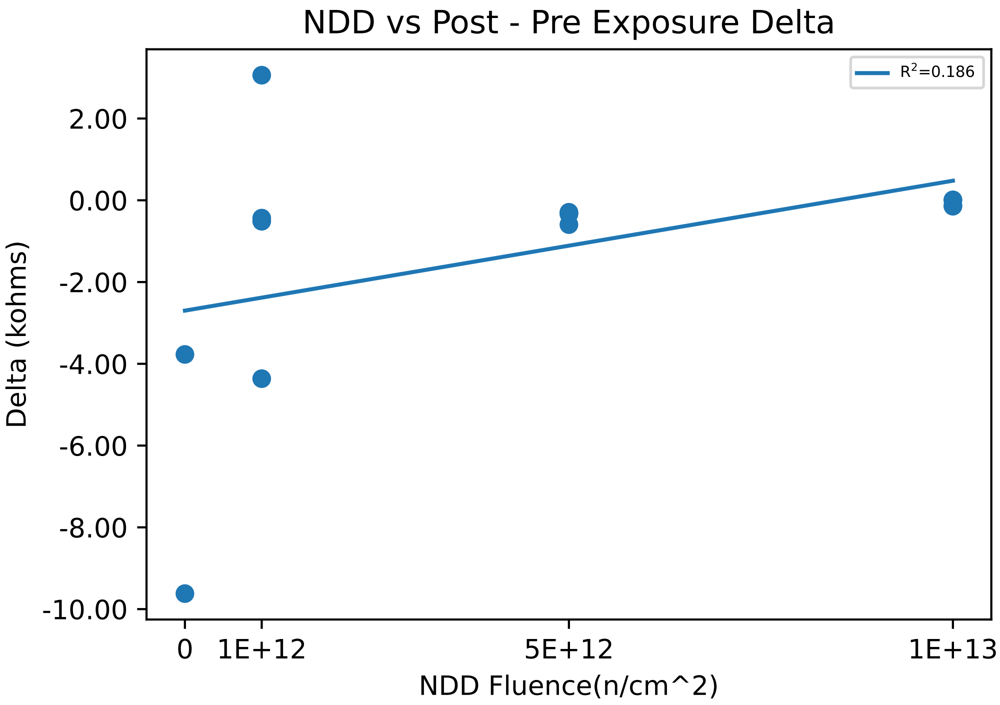
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	1.48	1.48	0
2	0	Correlation	1.48	1.48	0
30	1e+12	NDD unbiased	1.5	1.48	-0.02
31	1e+12	NDD unbiased	1.5	1.5	0
32	1e+12	NDD unbiased	1.48	1.48	0
33	1e+12	NDD unbiased	1.48	1.48	0
44	5e+12	NDD unbiased	1.48	1.48	0
45	5e+12	NDD unbiased	1.48	1.48	0
46	5e+12	NDD unbiased	1.48	1.5	0.02
47	5e+12	NDD unbiased	1.48	1.48	0
50	1e+13	NDD unbiased	1.48	1.48	0
51	1e+13	NDD unbiased	1.48	1.48	0
52	1e+13	NDD unbiased	1.48	1.48	0
53	1e+13	NDD unbiased	1.48	1.48	0

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.48	1.48	1.48	0	1.48	1.48	1.48	0	0	0	0	0
1e+12	1.48	1.49	1.5	0.011547	1.48	1.485	1.5	0.01	-0.02	-0.005	0	0.01
5e+12	1.48	1.48	1.48	0	1.48	1.485	1.5	0.01	0	0.005	0.02	0.01
1e+13	1.48	1.48	1.48	0	1.48	1.48	1.48	0	0	0	0	0

Device Test: 91.6 R_PD(_PWM_LI Pull Down Resistance VIN_12V)





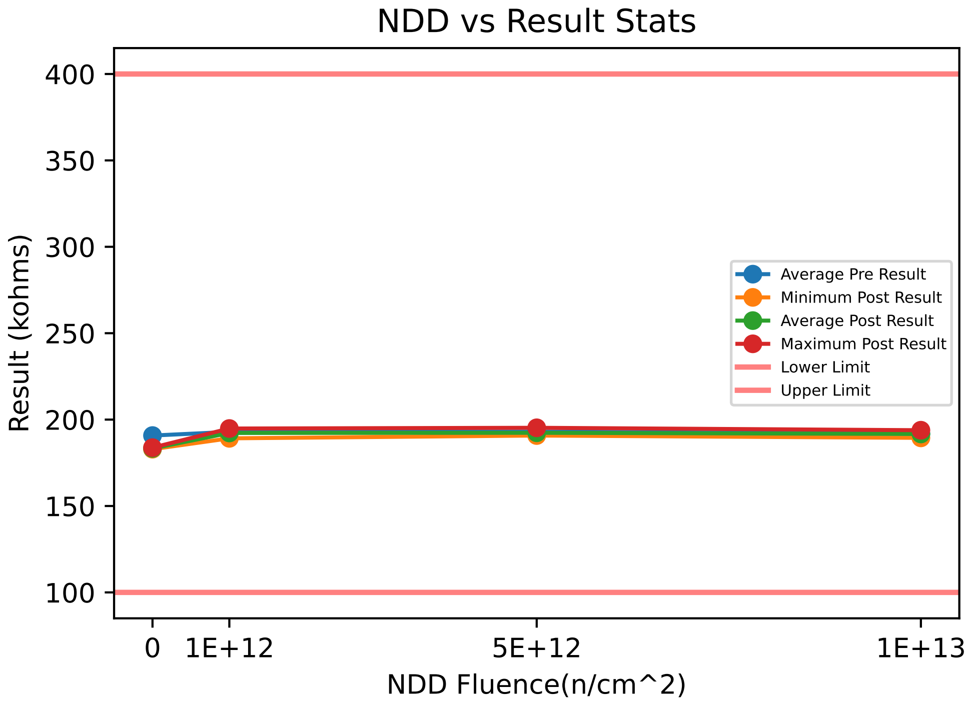
Test Results (Lower Limit = 100.0, Upper Limit = 400.0 (kohms))

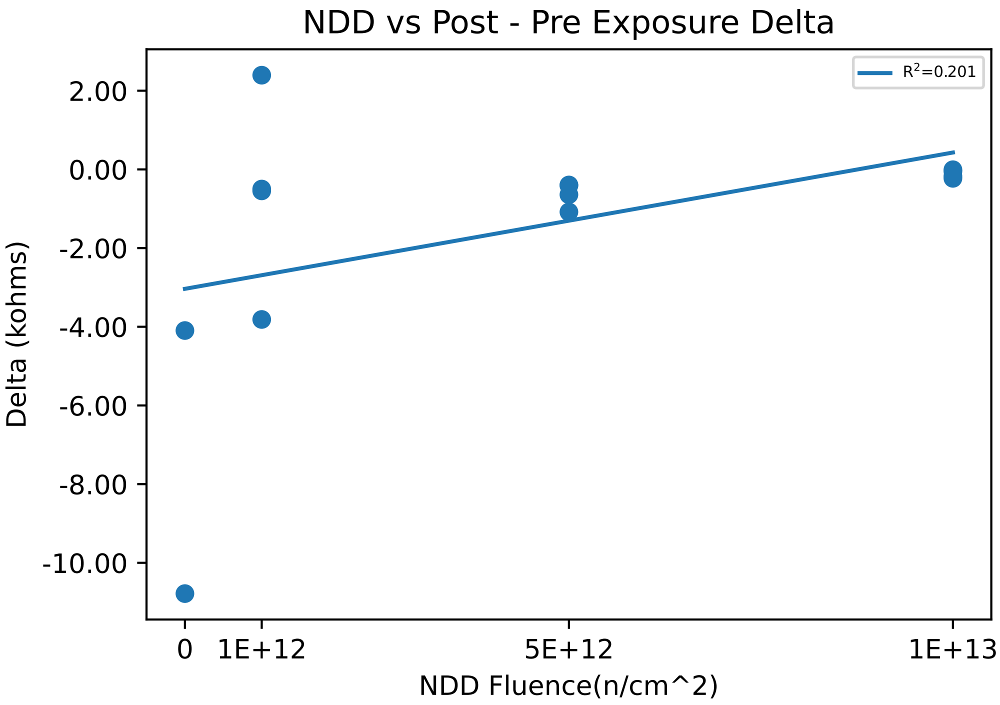
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	194.28	184.66	-9.6205
2	0	Correlation	188.97	185.2	-3.7708
30	1e+12	NDD unbiased	196.33	191.97	-4.3631
31	1e+12	NDD unbiased	192.69	195.75	3.0595
32	1e+12	NDD unbiased	189.89	189.46	-0.4363
33	1e+12	NDD unbiased	196.82	196.3	-0.5135
44	5e+12	NDD unbiased	194.72	194.12	-0.5953
45	5e+12	NDD unbiased	192.49	192.2	-0.293
46	5e+12	NDD unbiased	196.55	196.23	-0.3178
47	5e+12	NDD unbiased	192.4	192.06	-0.3368
50	1e+13	NDD unbiased	193.56	193.57	0.0098
51	1e+13	NDD unbiased	191.42	191.27	-0.1456
52	1e+13	NDD unbiased	194.97	194.98	0.005
53	1e+13	NDD unbiased	189.43	189.3	-0.1313

Test Statistics (kohms)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	188.97	191.63	194.28	3.7581	184.66	184.93	185.2	0.3783	-9.6205	-6.6956	-3.7708	4.1364
1e+12	189.89	193.93	196.82	3.262	189.46	193.37	196.3	3.2426	-4.3631	-0.56335	3.0595	3.0321
5e+12	192.4	194.04	196.55	1.9857	192.06	193.65	196.23	1.9578	-0.5953	-0.38573	-0.293	0.14086
1e+13	189.43	192.35	194.97	2.4319	189.3	192.28	194.98	2.5067	-0.1456	-0.065525	0.0098	0.084431

Device Test: 91.7 R_PD(_EN_HI Pull Down Resistance VIN_12V)





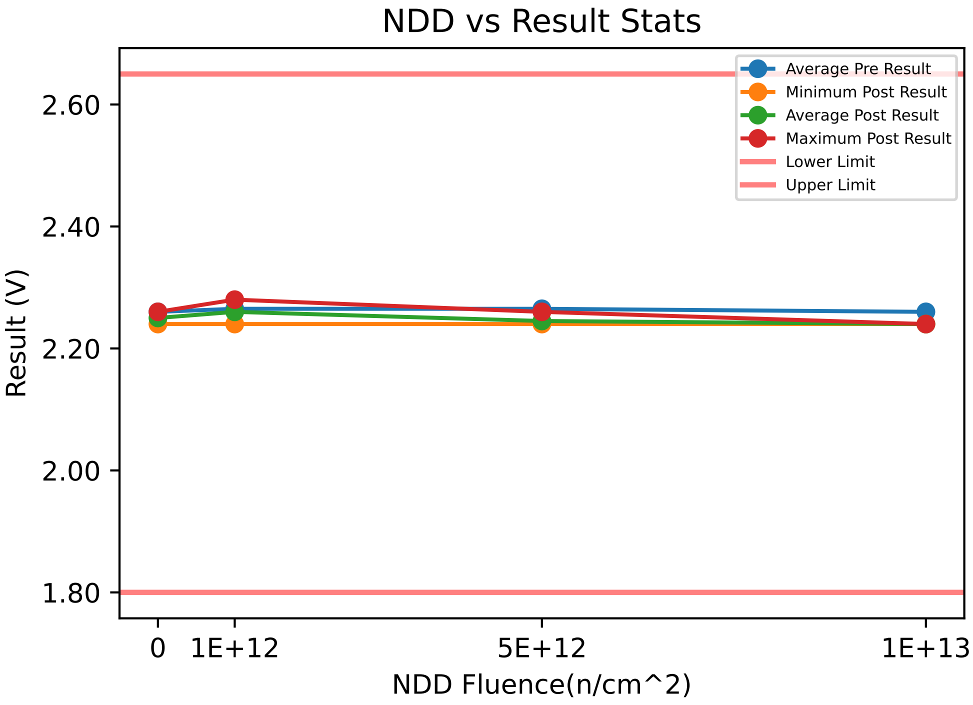
Test Results (Lower Limit = 100.0, Upper Limit = 400.0 (kohms))

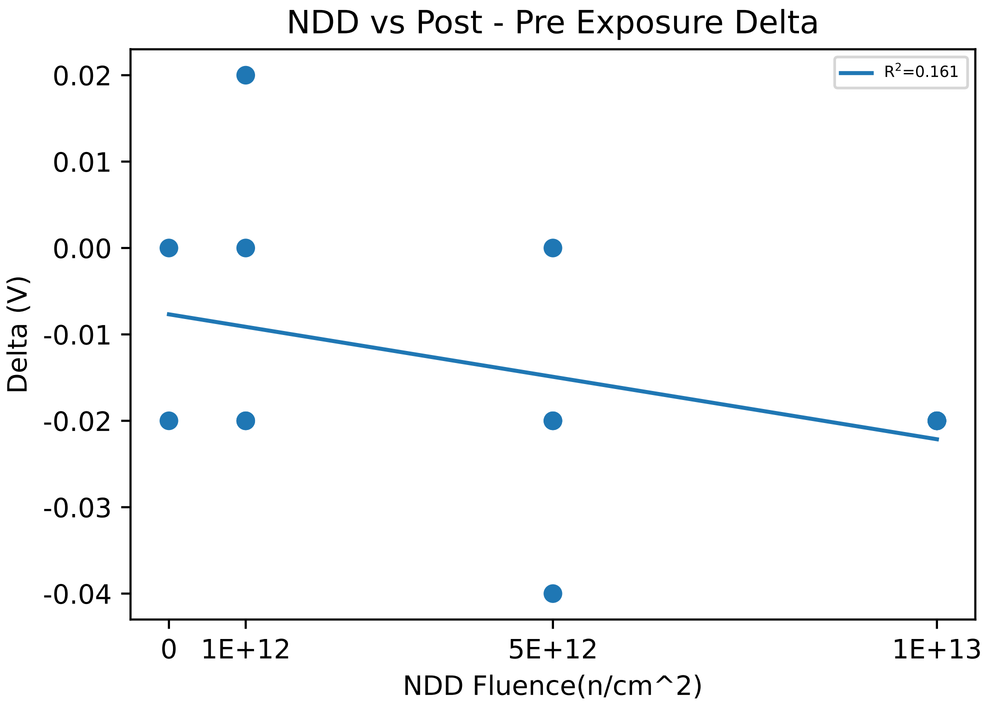
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	193.67	182.89	-10.782
2	0	Correlation	187.87	183.77	-4.0957
30	1e+12	NDD unbiased	194.76	190.94	-3.8143
31	1e+12	NDD unbiased	191.72	194.12	2.3946
32	1e+12	NDD unbiased	189.65	189.15	-0.4996
33	1e+12	NDD unbiased	195.39	194.84	-0.5455
44	5e+12	NDD unbiased	193.19	192.54	-0.6421
45	5e+12	NDD unbiased	191.98	190.89	-1.0817
46	5e+12	NDD unbiased	195.66	195.26	-0.4076
47	5e+12	NDD unbiased	191.17	190.77	-0.3958
50	1e+13	NDD unbiased	193.5	193.49	-0.0085
51	1e+13	NDD unbiased	190.16	189.94	-0.2271
52	1e+13	NDD unbiased	193.91	193.85	-0.051
53	1e+13	NDD unbiased	189.6	189.43	-0.1684

Test Statistics (kohms)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	187.87	190.77	193.67	4.1079	182.89	183.33	183.77	0.62034	-10.782	-7.4391	-4.0957	4.7282
1e+12	189.65	192.88	195.39	2.68	189.15	192.26	194.84	2.6763	-3.8143	-0.6162	2.3946	2.5371
5e+12	191.17	193	195.66	1.9606	190.77	192.37	195.26	2.0889	-1.0817	-0.6318	-0.3958	0.32066
1e+13	189.6	191.79	193.91	2.226	189.43	191.68	193.85	2.3188	-0.2271	-0.11375	-0.0085	0.10141

Device Test: 92.0 V_IH(_PWM_LI Rise Thresh VIN_14V)





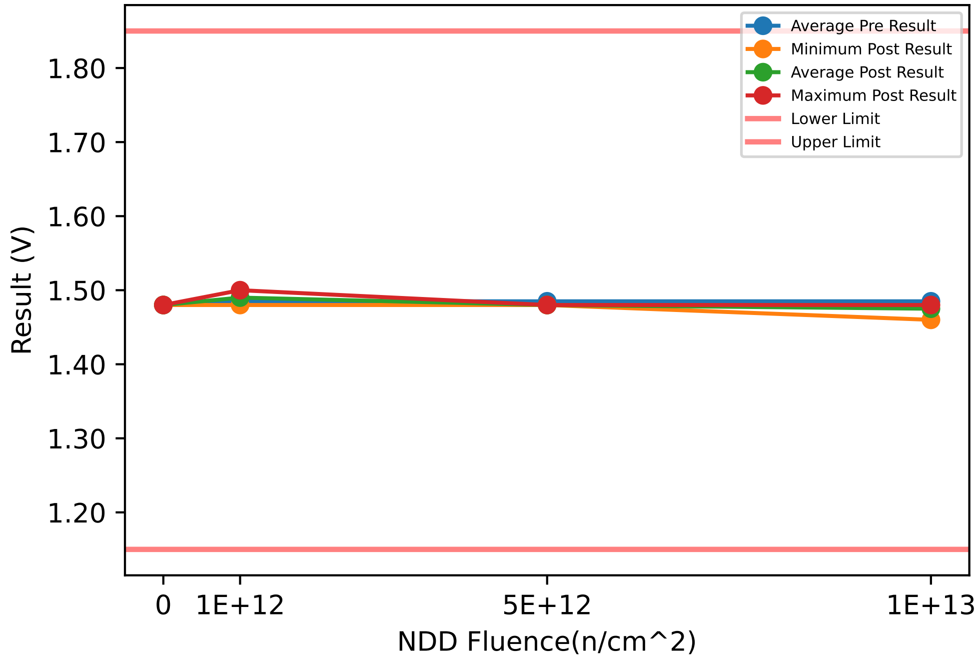
Test Results (Lower Limit = 1.8, Upper Limit = 2.65 (V))

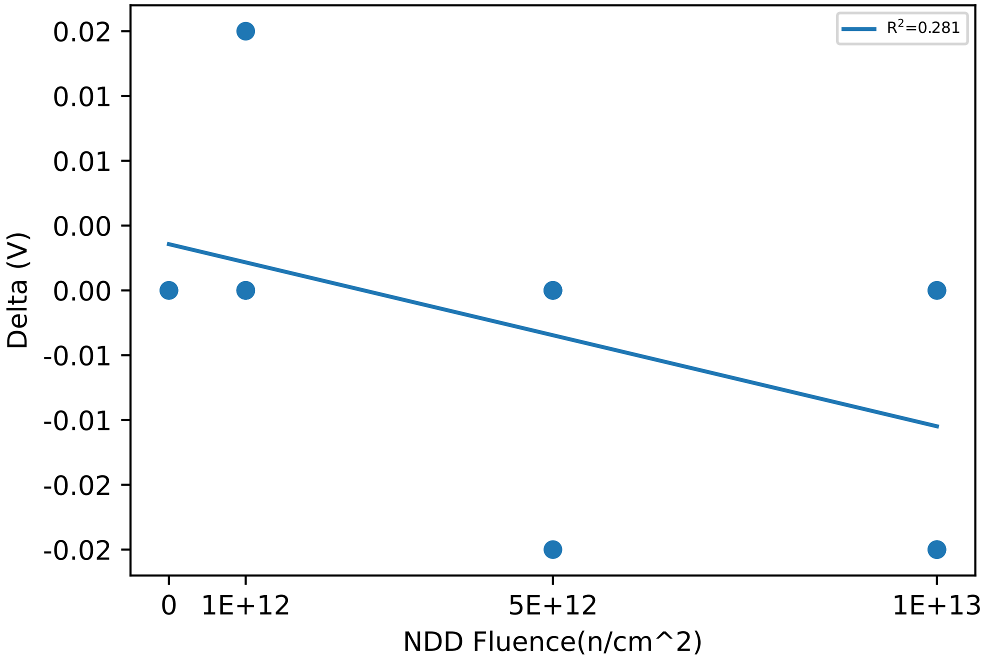
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	2.26	2.24	-0.02
2	0	Correlation	2.26	2.26	0
30	1e+12	NDD unbiased	2.28	2.26	-0.02
31	1e+12	NDD unbiased	2.26	2.28	0.02
32	1e+12	NDD unbiased	2.26	2.24	-0.02
33	1e+12	NDD unbiased	2.26	2.26	0
44	5e+12	NDD unbiased	2.26	2.26	0
45	5e+12	NDD unbiased	2.28	2.24	-0.04
46	5e+12	NDD unbiased	2.26	2.24	-0.02
47	5e+12	NDD unbiased	2.26	2.24	-0.02
50	1e+13	NDD unbiased	2.26	2.24	-0.02
51	1e+13	NDD unbiased	2.26	2.24	-0.02
52	1e+13	NDD unbiased	2.26	2.24	-0.02
53	1e+13	NDD unbiased	2.26	2.24	-0.02

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.26	2.26	2.26	0	2.24	2.25	2.26	0.014142	-0.02	-0.01	0	0.014142
1e+12	2.26	2.265	2.28	0.01	2.24	2.26	2.28	0.01633	-0.02	-0.005	0.02	0.019149
5e+12	2.26	2.265	2.28	0.01	2.24	2.245	2.26	0.01	-0.04	-0.02	0	0.01633
1e+13	2.26	2.26	2.26	0	2.24	2.24	2.24	0	-0.02	-0.02	-0.02	0

Device Test: 92.1 V_IL(_PWM_LI Fall Thresh VIN_14V)


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

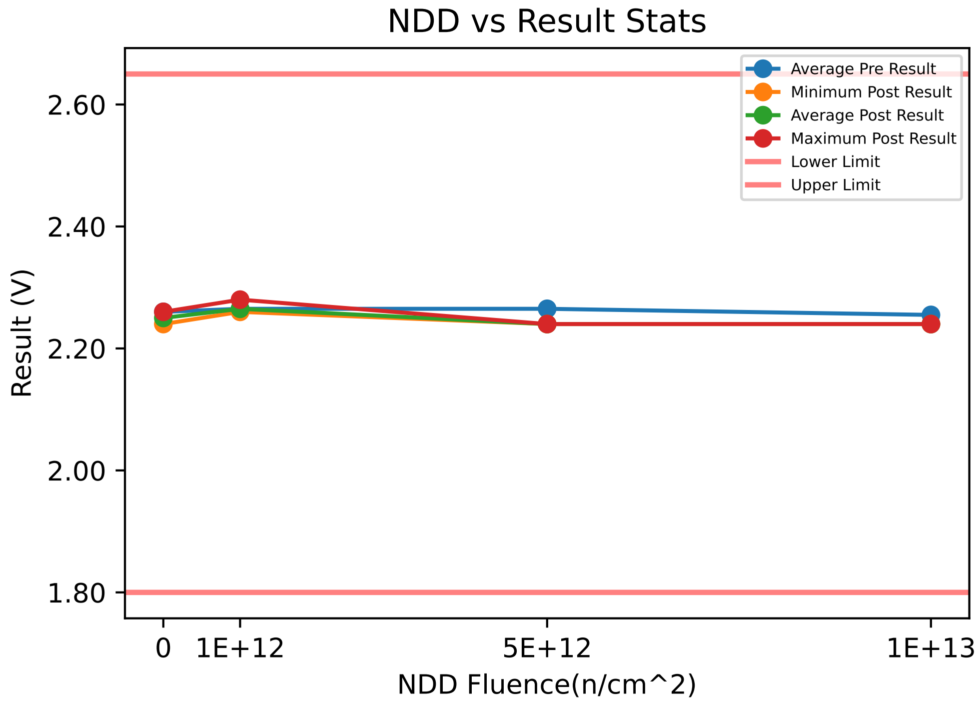
Test Results (Lower Limit = 1.15, Upper Limit = 1.85 (V))

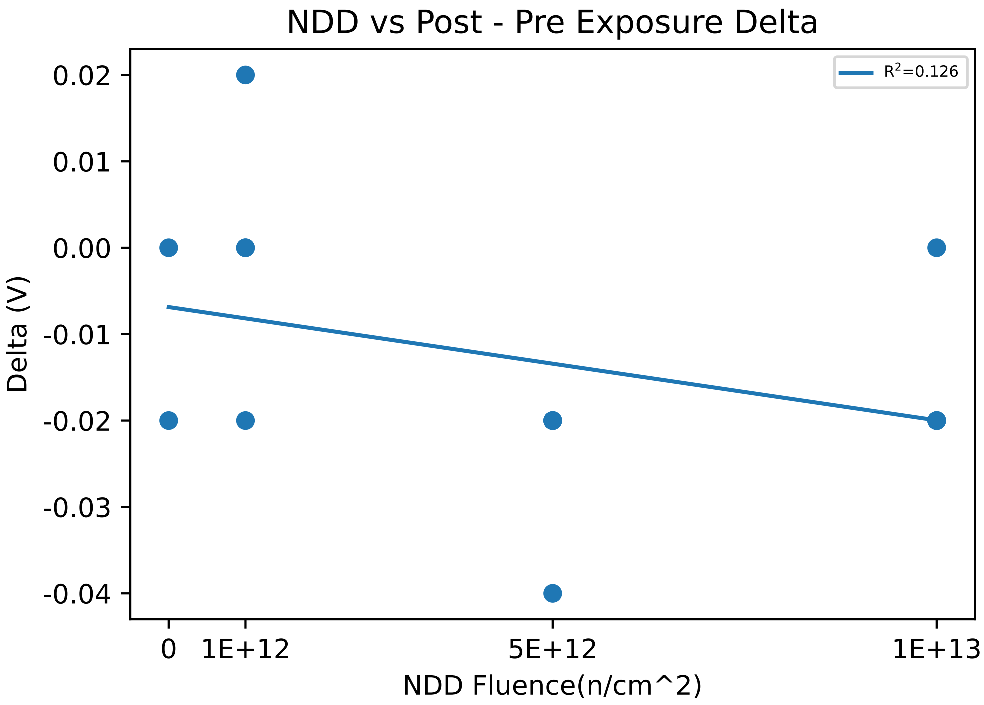
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	1.48	1.48	0
2	0	Correlation	1.48	1.48	0
30	1e+12	NDD unbiased	1.5	1.5	0
31	1e+12	NDD unbiased	1.48	1.5	0.02
32	1e+12	NDD unbiased	1.48	1.48	0
33	1e+12	NDD unbiased	1.48	1.48	0
44	5e+12	NDD unbiased	1.48	1.48	0
45	5e+12	NDD unbiased	1.5	1.48	-0.02
46	5e+12	NDD unbiased	1.48	1.48	0
47	5e+12	NDD unbiased	1.48	1.48	0
50	1e+13	NDD unbiased	1.48	1.48	0
51	1e+13	NDD unbiased	1.48	1.46	-0.02
52	1e+13	NDD unbiased	1.48	1.48	0
53	1e+13	NDD unbiased	1.5	1.48	-0.02

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.48	1.48	1.48	0	1.48	1.48	1.48	0	0	0	0	0
1e+12	1.48	1.485	1.5	0.01	1.48	1.49	1.5	0.011547	0	0.005	0.02	0.01
5e+12	1.48	1.485	1.5	0.01	1.48	1.48	1.48	0	-0.02	-0.005	0	0.01
1e+13	1.48	1.485	1.5	0.01	1.46	1.475	1.48	0.01	-0.02	-0.01	0	0.011547

Device Test: 92.3 V_IH(_EN_HI Rise Thresh VIN_14V)





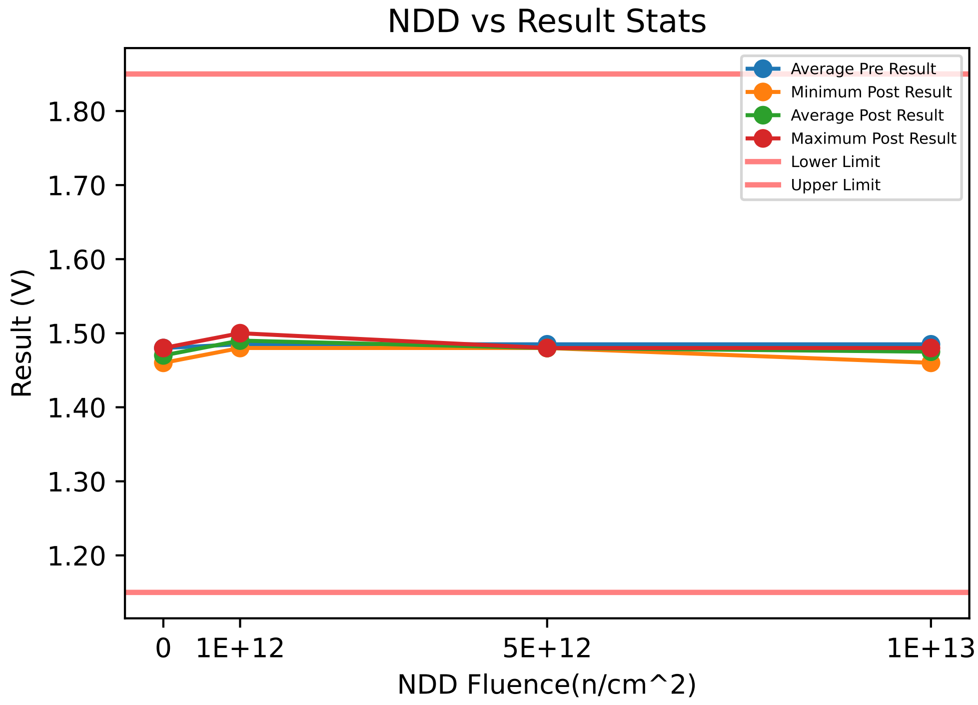
Test Results (Lower Limit = 1.8, Upper Limit = 2.65 (V))

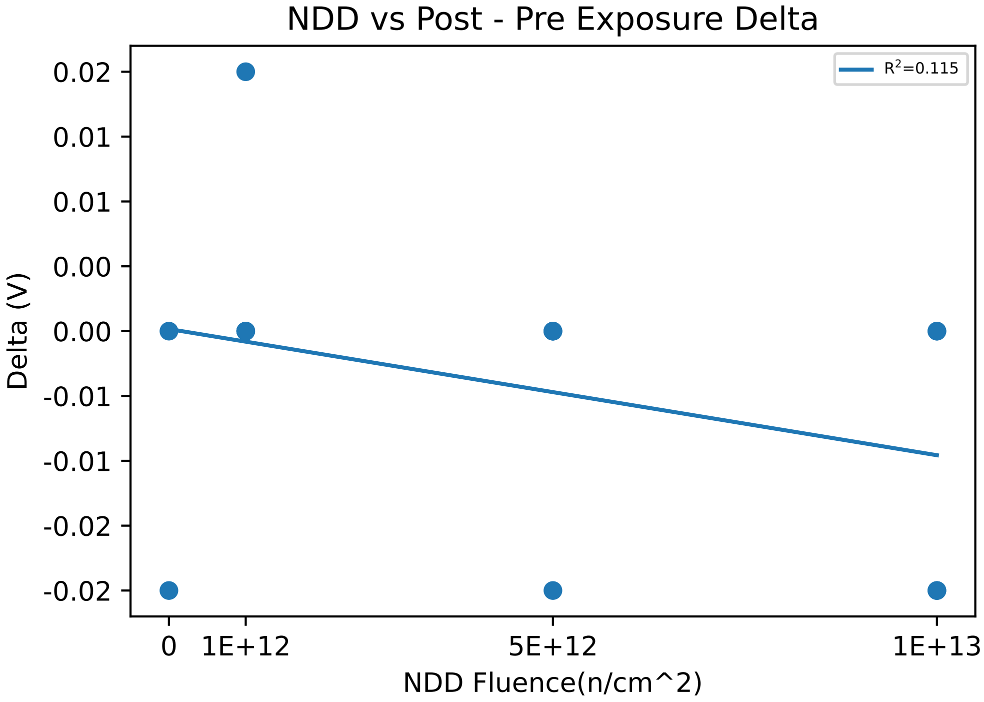
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	2.26	2.24	-0.02
2	0	Correlation	2.26	2.26	0
30	1e+12	NDD unbiased	2.28	2.26	-0.02
31	1e+12	NDD unbiased	2.26	2.28	0.02
32	1e+12	NDD unbiased	2.26	2.26	0
33	1e+12	NDD unbiased	2.26	2.26	0
44	5e+12	NDD unbiased	2.26	2.24	-0.02
45	5e+12	NDD unbiased	2.28	2.24	-0.04
46	5e+12	NDD unbiased	2.26	2.24	-0.02
47	5e+12	NDD unbiased	2.26	2.24	-0.02
50	1e+13	NDD unbiased	2.26	2.24	-0.02
51	1e+13	NDD unbiased	2.24	2.24	0
52	1e+13	NDD unbiased	2.26	2.24	-0.02
53	1e+13	NDD unbiased	2.26	2.24	-0.02

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.26	2.26	2.26	0	2.24	2.25	2.26	0.014142	-0.02	-0.01	0	0.014142
1e+12	2.26	2.265	2.28	0.01	2.26	2.265	2.28	0.01	-0.02	0	0.02	0.01633
5e+12	2.26	2.265	2.28	0.01	2.24	2.24	2.24	0	-0.04	-0.025	-0.02	0.01
1e+13	2.24	2.255	2.26	0.01	2.24	2.24	2.24	0	-0.02	-0.015	0	0.01

Device Test: 92.4 V_IL(_EN_HI Fall Thresh VIN_14V)





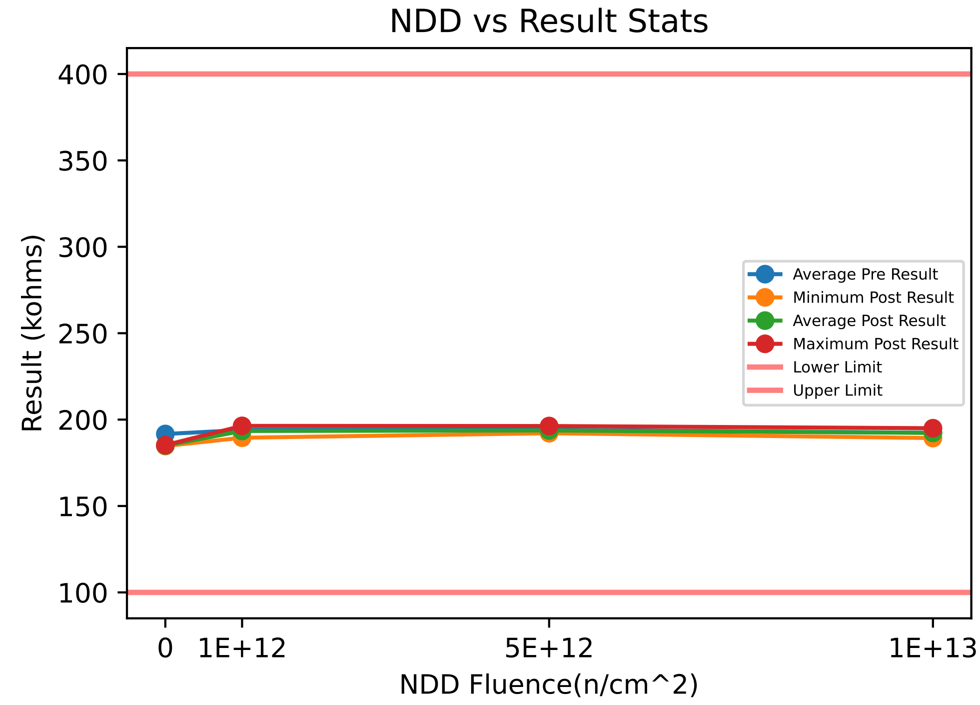
Test Results (Lower Limit = 1.15, Upper Limit = 1.85 (V))

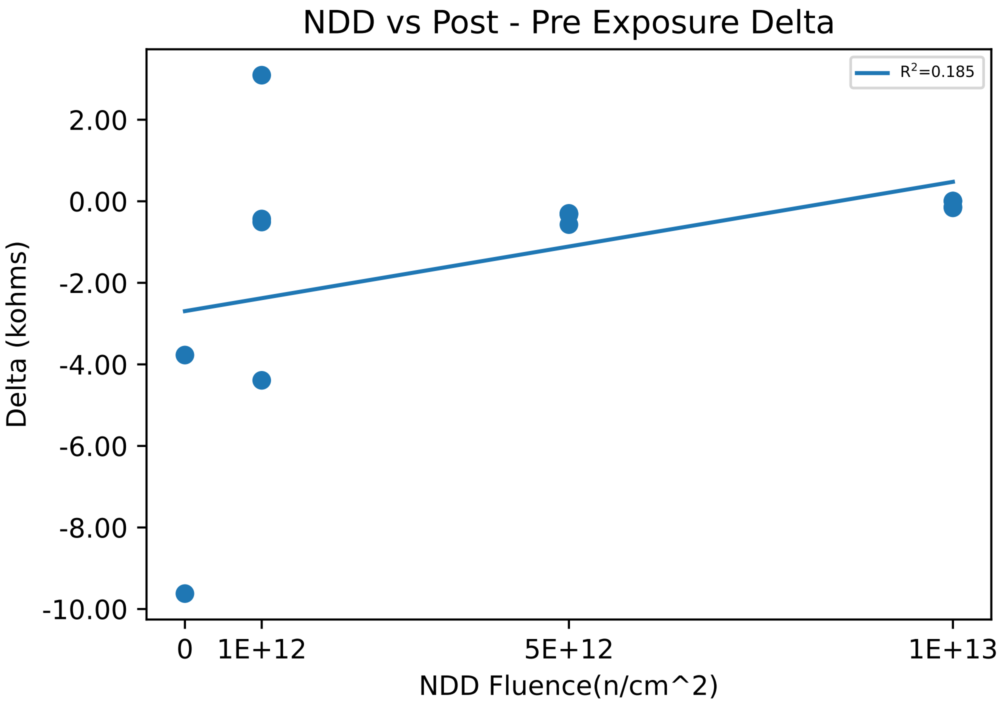
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	1.48	1.46	-0.02
2	0	Correlation	1.48	1.48	0
30	1e+12	NDD unbiased	1.5	1.5	0
31	1e+12	NDD unbiased	1.48	1.5	0.02
32	1e+12	NDD unbiased	1.48	1.48	0
33	1e+12	NDD unbiased	1.48	1.48	0
44	5e+12	NDD unbiased	1.48	1.48	0
45	5e+12	NDD unbiased	1.5	1.48	-0.02
46	5e+12	NDD unbiased	1.48	1.48	0
47	5e+12	NDD unbiased	1.48	1.48	0
50	1e+13	NDD unbiased	1.48	1.46	-0.02
51	1e+13	NDD unbiased	1.48	1.48	0
52	1e+13	NDD unbiased	1.5	1.48	-0.02
53	1e+13	NDD unbiased	1.48	1.48	0

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.48	1.48	1.48	0	1.46	1.47	1.48	0.014142	-0.02	-0.01	0	0.014142
1e+12	1.48	1.485	1.5	0.01	1.48	1.49	1.5	0.011547	0	0.005	0.02	0.01
5e+12	1.48	1.485	1.5	0.01	1.48	1.48	1.48	0	-0.02	-0.005	0	0.01
1e+13	1.48	1.485	1.5	0.01	1.46	1.475	1.48	0.01	-0.02	-0.01	0	0.011547

Device Test: 92.6 R_PD(_PWM_LI Pull Down Resistance VIN_14V)





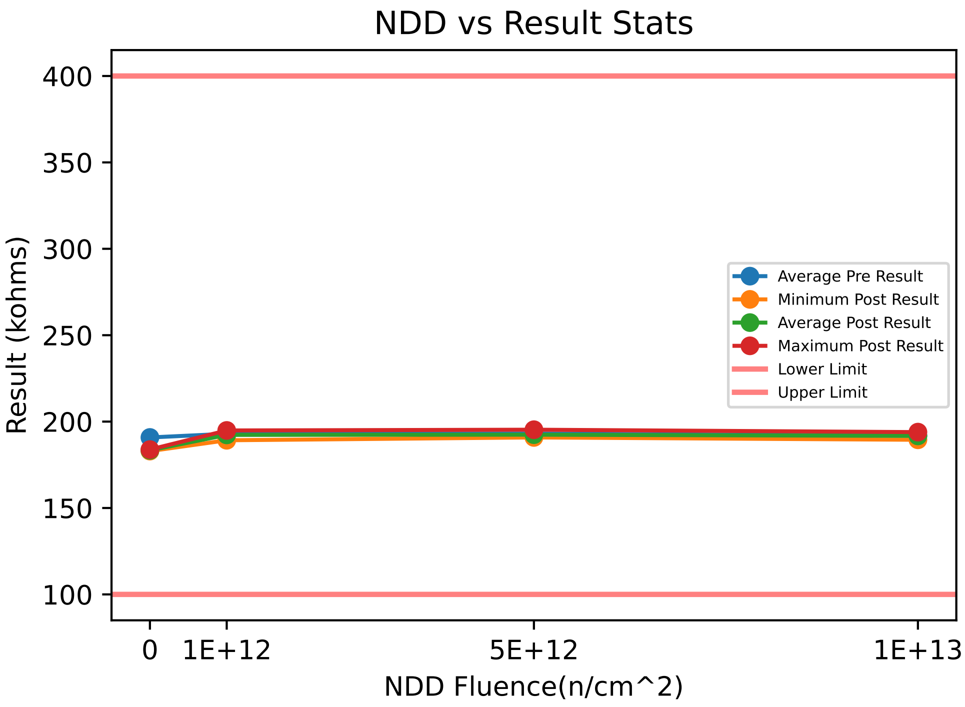
Test Results (Lower Limit = 100.0, Upper Limit = 400.0 (kohms))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	194.33	184.7	-9.6215
2	0	Correlation	189.01	185.24	-3.7714
30	1e+12	NDD unbiased	196.38	191.99	-4.3913
31	1e+12	NDD unbiased	192.71	195.81	3.092
32	1e+12	NDD unbiased	189.94	189.51	-0.4343
33	1e+12	NDD unbiased	196.87	196.36	-0.509
44	5e+12	NDD unbiased	194.75	194.18	-0.5724
45	5e+12	NDD unbiased	192.53	192.24	-0.2965
46	5e+12	NDD unbiased	196.59	196.28	-0.3085
47	5e+12	NDD unbiased	192.44	192.12	-0.3268
50	1e+13	NDD unbiased	193.6	193.6	0.0041
51	1e+13	NDD unbiased	191.46	191.3	-0.1613
52	1e+13	NDD unbiased	195	195.01	0.0073
53	1e+13	NDD unbiased	189.46	189.33	-0.1347

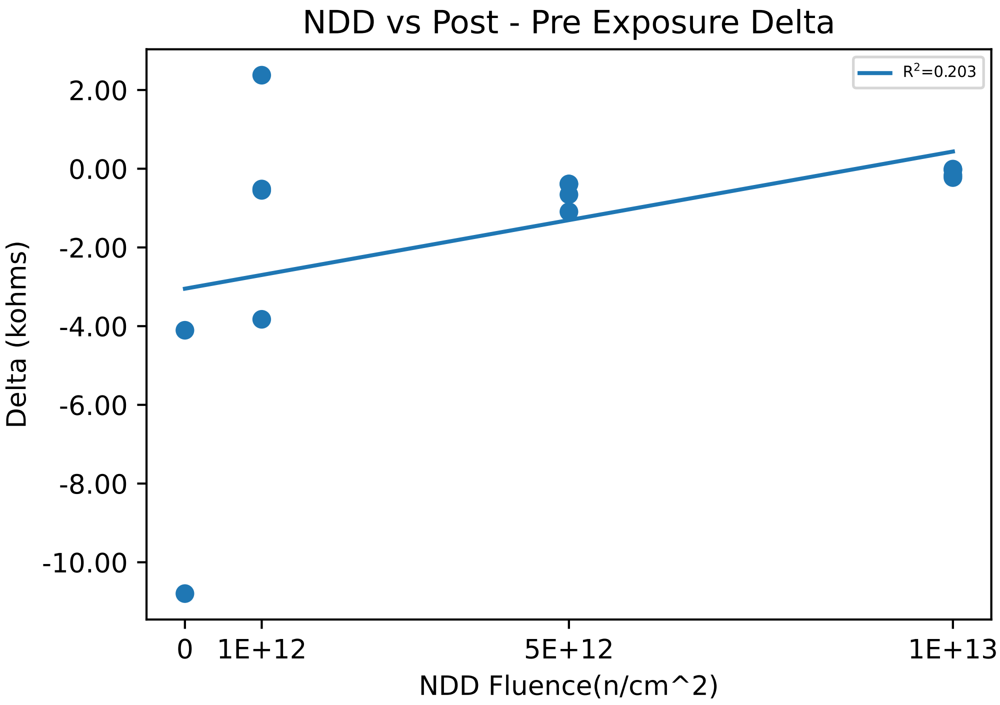
Test Statistics (kohms)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	189.01	191.67	194.33	3.7574	184.7	184.97	185.24	0.37922	-9.6215	-6.6964	-3.7714	4.1366
1e+12	189.94	193.98	196.87	3.2669	189.51	193.42	196.36	3.2501	-4.3913	-0.56065	3.092	3.0569
5e+12	192.44	194.08	196.59	1.9857	192.12	193.7	196.28	1.9621	-0.5724	-0.37605	-0.2965	0.13149
1e+13	189.46	192.38	195	2.4297	189.33	192.31	195.01	2.5077	-0.1613	-0.07115	0.0073	0.08941

Device Test: 92.7 R_PD(_EN_HI Pull Down Resistance VIN_14V)



NDD vs Result Stats



NDD vs Post - Pre Exposure Delta

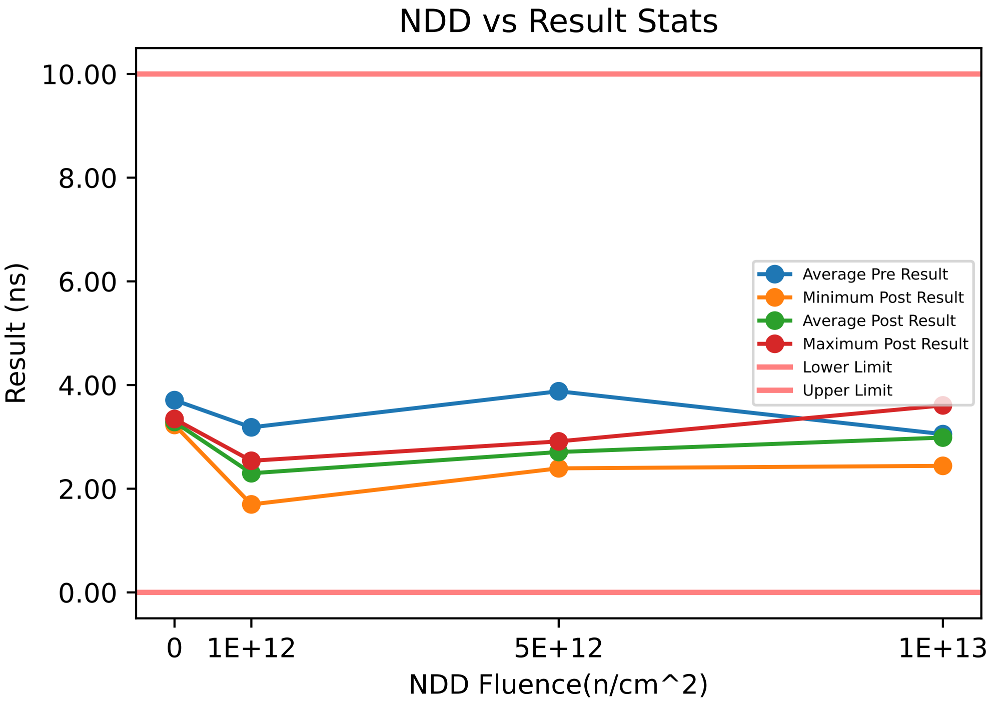
Test Results (Lower Limit = 100.0,
Upper Limit = 400.0 (kohms))

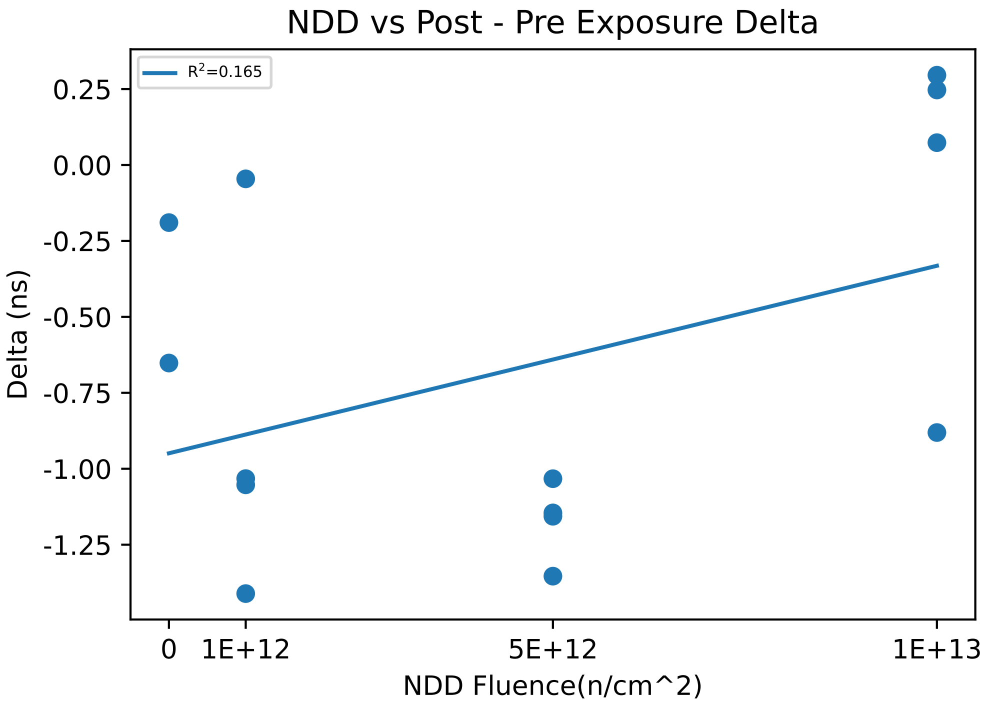
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	193.74	182.94	-10.796
2	0	Correlation	187.91	183.8	-4.1047
30	1e+12	NDD unbiased	194.81	190.98	-3.8264
31	1e+12	NDD unbiased	191.77	194.15	2.3764
32	1e+12	NDD unbiased	189.71	189.19	-0.5153
33	1e+12	NDD unbiased	195.43	194.88	-0.5503
44	5e+12	NDD unbiased	193.24	192.58	-0.6582
45	5e+12	NDD unbiased	192.03	190.94	-1.0935
46	5e+12	NDD unbiased	195.69	195.31	-0.3889
47	5e+12	NDD unbiased	191.22	190.83	-0.387
50	1e+13	NDD unbiased	193.53	193.52	-0.0097
51	1e+13	NDD unbiased	190.2	189.97	-0.2249
52	1e+13	NDD unbiased	193.94	193.91	-0.0303
53	1e+13	NDD unbiased	189.63	189.47	-0.1651

Test Statistics (kohms)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	187.91	190.82	193.74	4.1219	182.94	183.37	183.8	0.60967	-10.796	-7.4504	-4.1047	4.7315
1e+12	189.71	192.93	195.43	2.6782	189.19	192.3	194.88	2.6743	-3.8264	-0.6289	2.3764	2.5348
5e+12	191.22	193.05	195.69	1.951	190.83	192.41	195.31	2.0876	-1.0935	-0.6319	-0.387	0.33306
1e+13	189.63	191.82	193.94	2.2227	189.47	191.72	193.91	2.3201	-0.2249	-0.1075	-0.0097	0.10428

Device Test: 95.0 T_RLH_MIN(_DLH Dead Time Min 500kHz VIN_10V)





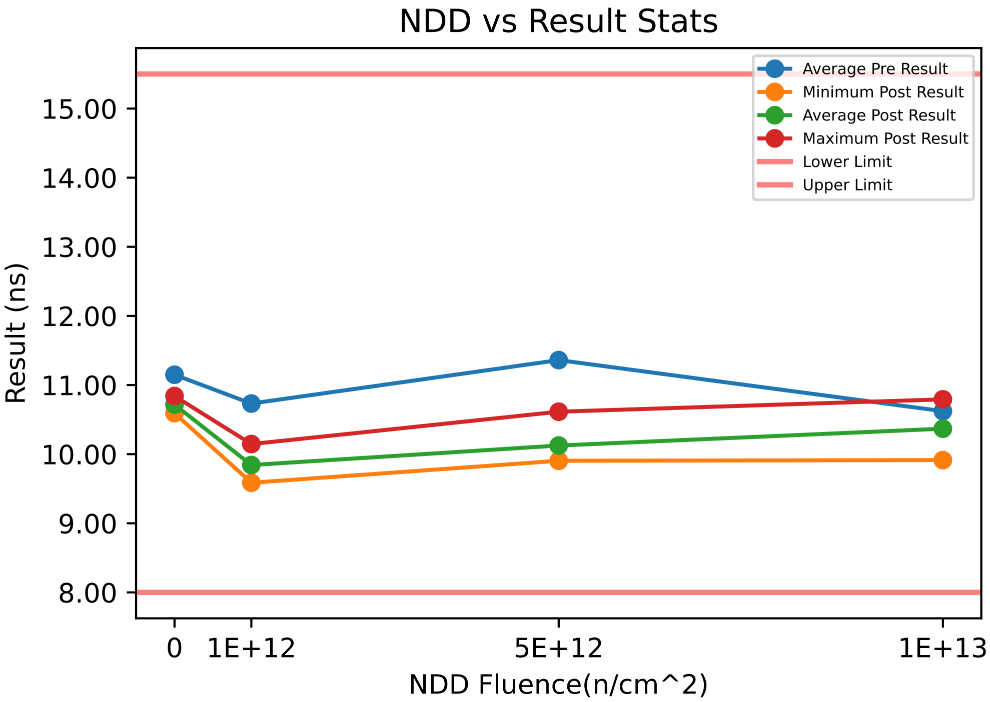
Test Results (Lower Limit = 0.0, Upper Limit = 10.0 (ns))

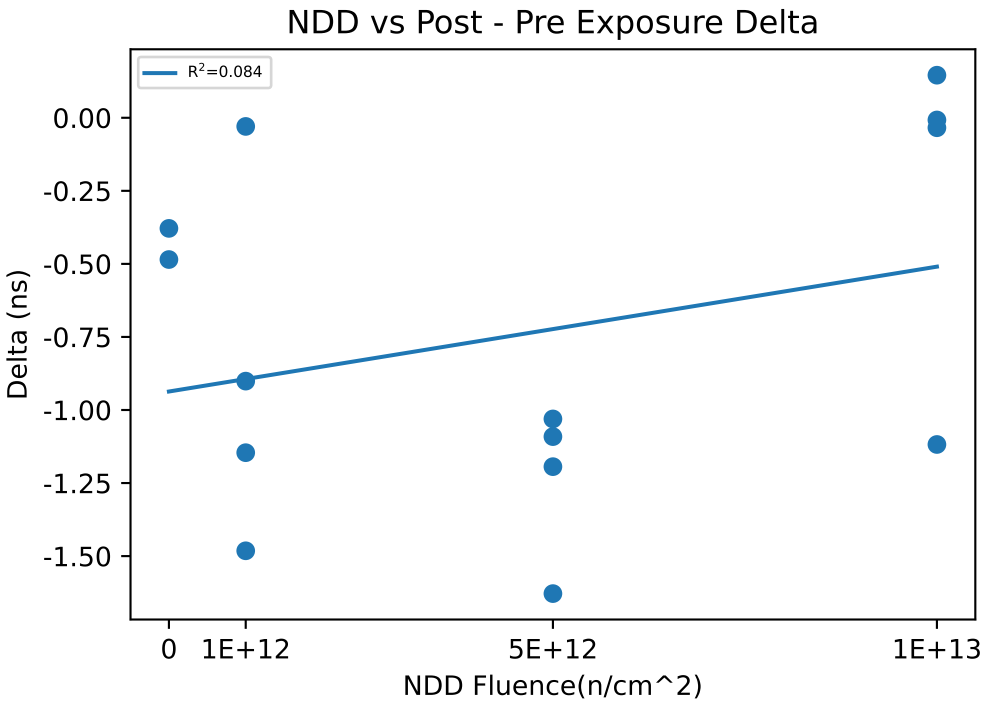
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	3.8816	3.2297	-0.6519
2	0	Correlation	3.5351	3.3455	-0.1896
30	1e+12	NDD unbiased	3.8413	2.4304	-1.4109
31	1e+12	NDD unbiased	3.5916	2.5388	-1.0528
32	1e+12	NDD unbiased	3.56	2.5276	-1.0324
33	1e+12	NDD unbiased	1.7429	1.6973	-0.0456
44	5e+12	NDD unbiased	3.5386	2.3933	-1.1453
45	5e+12	NDD unbiased	3.9561	2.7998	-1.1563
46	5e+12	NDD unbiased	3.9456	2.9129	-1.0327
47	5e+12	NDD unbiased	4.0793	2.7258	-1.3535
50	1e+13	NDD unbiased	2.3677	2.4412	0.0735
51	1e+13	NDD unbiased	4.4879	3.6072	-0.8807
52	1e+13	NDD unbiased	2.5093	2.7563	0.247
53	1e+13	NDD unbiased	2.8461	3.1417	0.2956

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.5351	3.7084	3.8816	0.24501	3.2297	3.2876	3.3455	0.081883	-0.6519	-0.42075	-0.1896	0.3269
1e+12	1.7429	3.1839	3.8413	0.9689	1.6973	2.2985	2.5388	0.40376	-1.4109	-0.88542	-0.0456	0.58624
5e+12	3.5386	3.8799	4.0793	0.23549	2.3933	2.7079	2.9129	0.22343	-1.3535	-1.172	-1.0327	0.1333
1e+13	2.3677	3.0528	4.4879	0.97758	2.4412	2.9866	3.6072	0.50322	-0.8807	-0.06615	0.2956	0.55134

Device Test: 95.1 T_RLH_SMALL(_DLH Dead Time Small 500kHz VIN_10V)





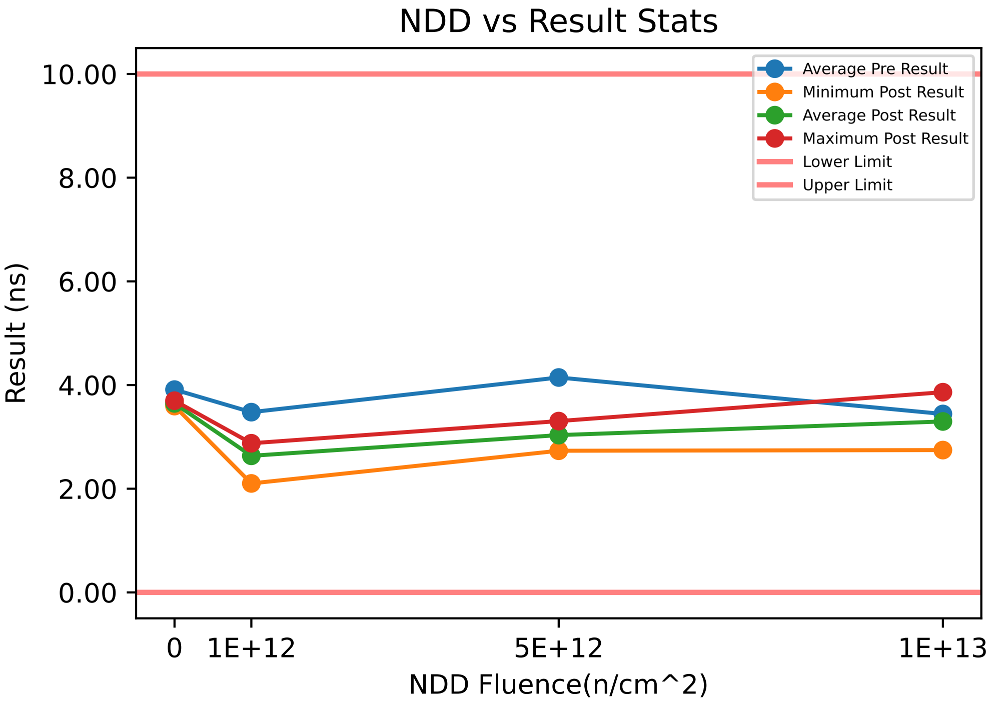
Test Results (Lower Limit = 8.0, Upper Limit = 15.5 (ns))

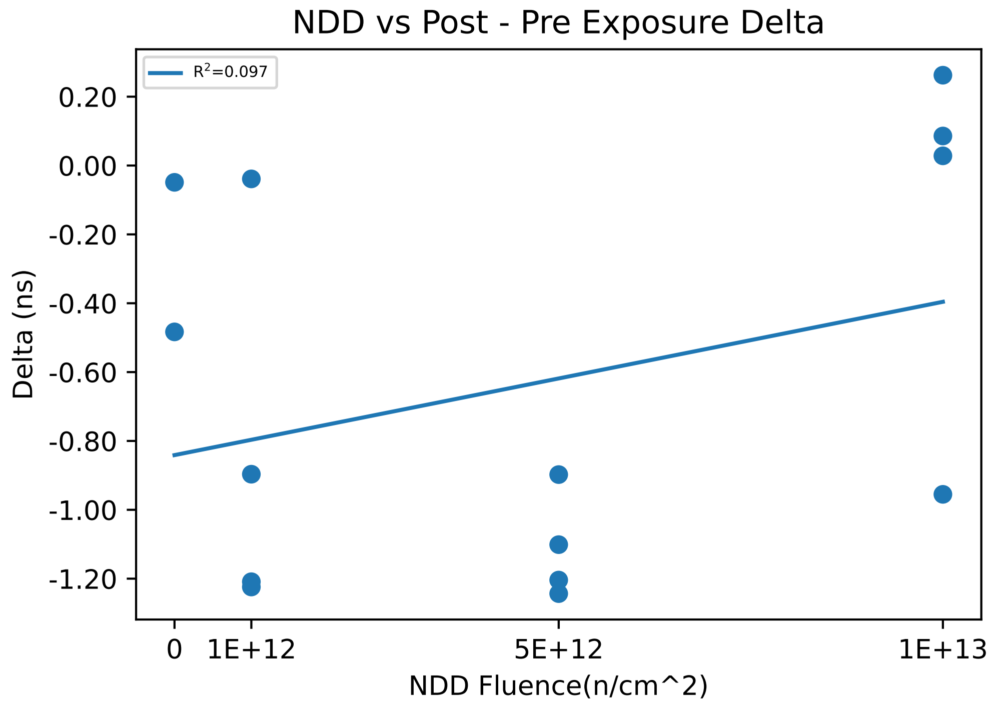
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	10.972	10.594	-0.3785
2	0	Correlation	11.326	10.841	-0.4851
30	1e+12	NDD unbiased	11.047	10.146	-0.9012
31	1e+12	NDD unbiased	11.354	9.8717	-1.4818
32	1e+12	NDD unbiased	10.913	9.767	-1.1461
33	1e+12	NDD unbiased	9.6159	9.5863	-0.0296
44	5e+12	NDD unbiased	11.053	10.023	-1.0306
45	5e+12	NDD unbiased	11.587	9.9584	-1.6283
46	5e+12	NDD unbiased	11.705	10.614	-1.0911
47	5e+12	NDD unbiased	11.098	9.9044	-1.1939
50	1e+13	NDD unbiased	9.9461	10.092	0.1457
51	1e+13	NDD unbiased	11.793	10.675	-1.118
52	1e+13	NDD unbiased	9.948	9.9139	-0.0341
53	1e+13	NDD unbiased	10.8	10.793	-0.0075

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	10.972	11.149	11.326	0.25039	10.594	10.717	10.841	0.17501	-0.4851	-0.4318	-0.3785	0.075378
1e+12	9.6159	10.732	11.354	0.76687	9.5863	9.8428	10.146	0.23415	-1.4818	-0.88967	-0.0296	0.62081
5e+12	11.053	11.361	11.705	0.33325	9.9044	10.125	10.614	0.32971	-1.6283	-1.236	-1.0306	0.2701
1e+13	9.9461	10.622	11.793	0.87839	9.9139	10.368	10.793	0.43108	-1.118	-0.25348	0.1457	0.58177

Device Test: 95.10 T_RLH_MIN(_DLH Dead Time Min 2MHz VIN_10V)


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

Test Results (Lower Limit = 0.0, Upper Limit = 10.0 (ns))

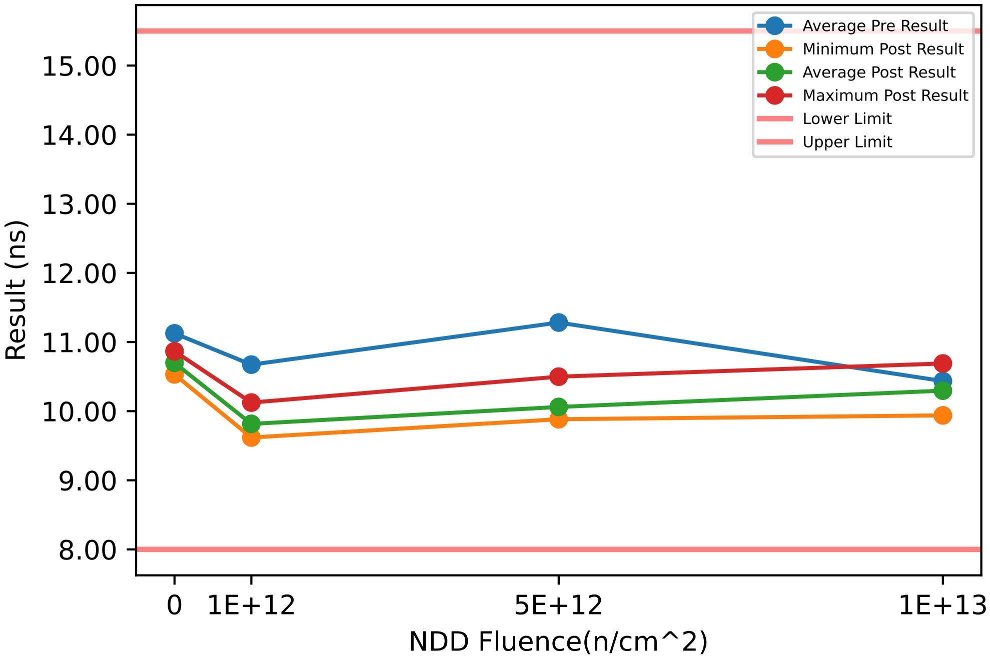
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	4.077	3.5938	-0.4832
2	0	Correlation	3.7471	3.6983	-0.0488
30	1e+12	NDD unbiased	3.9162	2.692	-1.2242
31	1e+12	NDD unbiased	3.7737	2.8771	-0.8966
32	1e+12	NDD unbiased	4.0768	2.8679	-1.2089
33	1e+12	NDD unbiased	2.1409	2.1021	-0.0388
44	5e+12	NDD unbiased	3.8335	2.7323	-1.1012
45	5e+12	NDD unbiased	4.2767	3.0333	-1.2434
46	5e+12	NDD unbiased	4.202	3.3043	-0.8977
47	5e+12	NDD unbiased	4.27	3.0659	-1.2041
50	1e+13	NDD unbiased	2.7171	2.7453	0.0282
51	1e+13	NDD unbiased	4.817	3.8619	-0.9551
52	1e+13	NDD unbiased	3.0045	3.0903	0.0858
53	1e+13	NDD unbiased	3.2289	3.4913	0.2624

Test Statistics (ns)

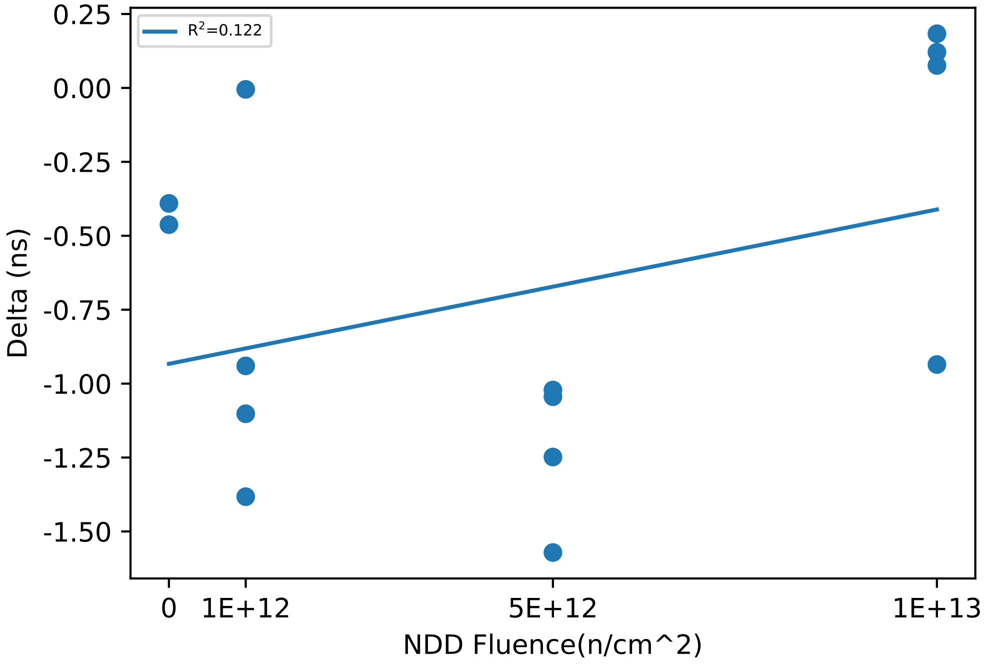
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.7471	3.912	4.077	0.23327	3.5938	3.646	3.6983	0.073893	-0.4832	-0.266	-0.0488	0.30717
1e+12	2.1409	3.4769	4.0768	0.89923	2.1021	2.6348	2.8771	0.36519	-1.2242	-0.84212	-0.0388	0.55642
5e+12	3.8335	4.1456	4.2767	0.21075	2.7323	3.0339	3.3043	0.23459	-1.2434	-1.1116	-0.8977	0.15469
1e+13	2.7171	3.4419	4.817	0.94038	2.7453	3.2972	3.8619	0.48441	-0.9551	-0.14468	0.2624	0.54939

Device Test: 95.11 T_RLH_SMALL(_DLH Dead Time Small 2MHz VIN_10V)

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



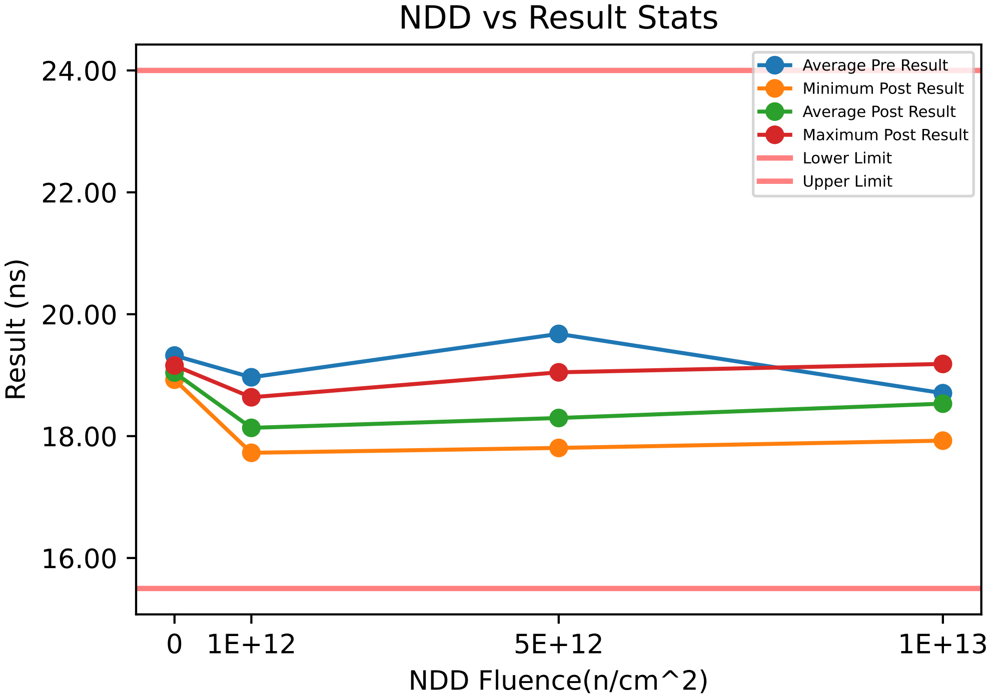
Test Results (Lower Limit = 8.0,
Upper Limit = 15.5 (ns))

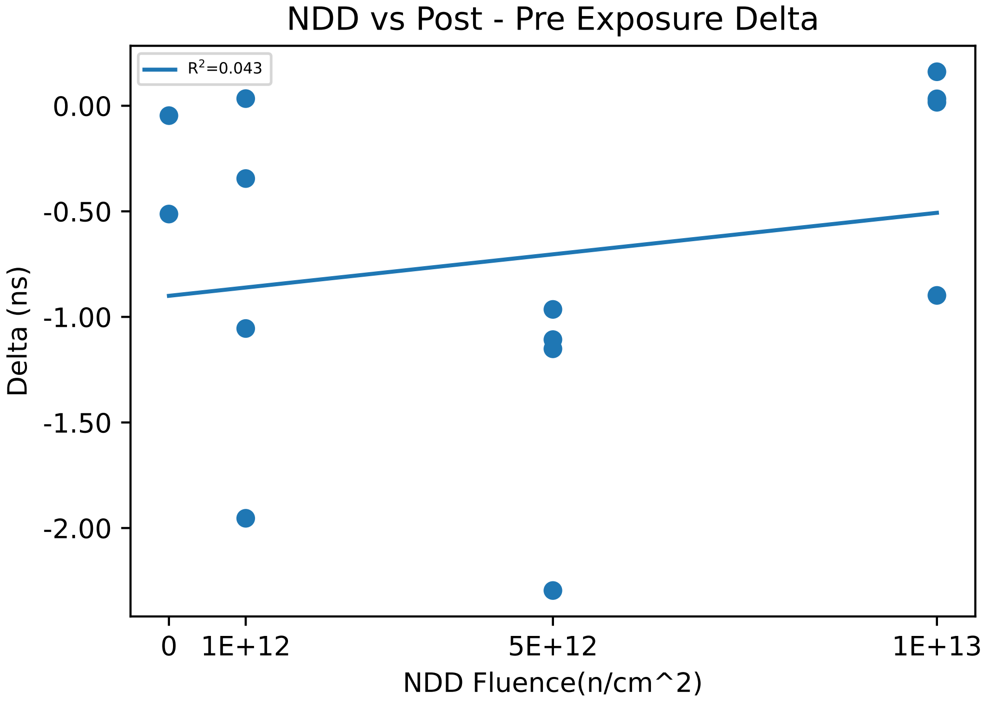
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	10.994	10.532	-0.4624
2	0	Correlation	11.257	10.866	-0.3905
30	1e+12	NDD unbiased	11.064	10.124	-0.94
31	1e+12	NDD unbiased	11.131	9.7482	-1.3824
32	1e+12	NDD unbiased	10.874	9.7718	-1.1019
33	1e+12	NDD unbiased	9.6239	9.619	-0.0049
44	5e+12	NDD unbiased	10.999	9.9548	-1.0442
45	5e+12	NDD unbiased	11.477	9.9059	-1.5712
46	5e+12	NDD unbiased	11.747	10.499	-1.2482
47	5e+12	NDD unbiased	10.905	9.8833	-1.0216
50	1e+13	NDD unbiased	9.8188	10.002	0.1833
51	1e+13	NDD unbiased	11.491	10.556	-0.9354
52	1e+13	NDD unbiased	9.8179	9.9386	0.1207
53	1e+13	NDD unbiased	10.614	10.69	0.076

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	10.994	11.126	11.257	0.18562	10.532	10.699	10.866	0.23646	-0.4624	-0.42645	-0.3905	0.050841
1e+12	9.6239	10.673	11.131	0.70787	9.619	9.8158	10.124	0.21624	-1.3824	-0.8573	-0.0049	0.59693
5e+12	10.905	11.282	11.747	0.39865	9.8833	10.061	10.499	0.29369	-1.5712	-1.2213	-1.0216	0.25456
1e+13	9.8179	10.435	11.491	0.79757	9.9386	10.297	10.69	0.38147	-0.9354	-0.13885	0.1833	0.53285

Device Test: 95.12 T_RLH_MID(_DLH Dead Time Mid 2MHz VIN_10V)


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

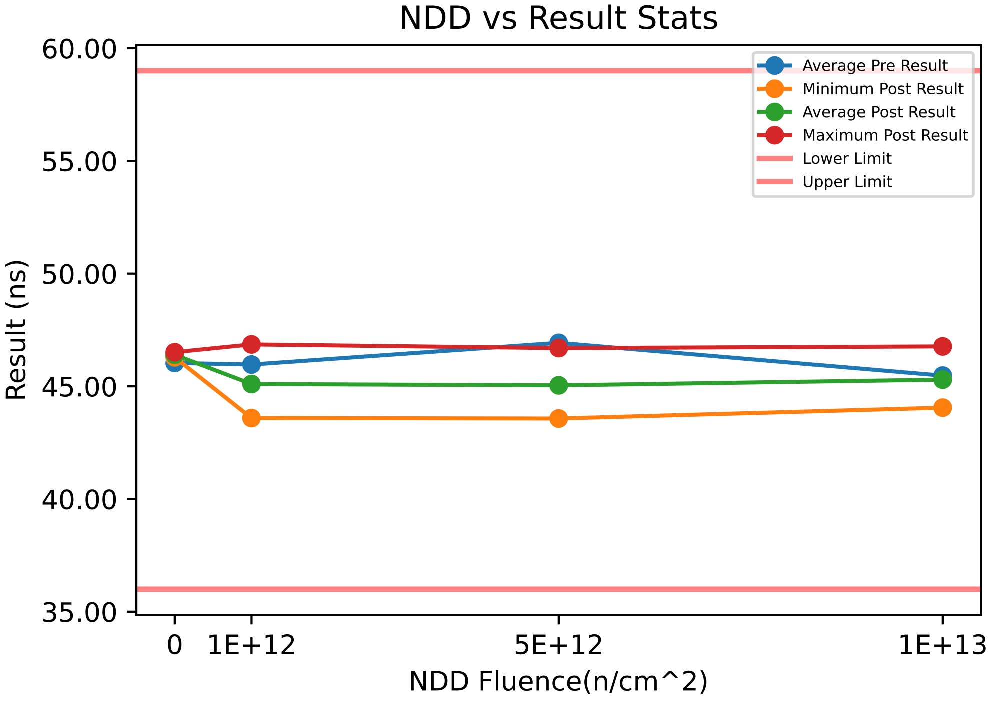
Test Results (Lower Limit = 15.5, Upper Limit = 24.0 (ns))

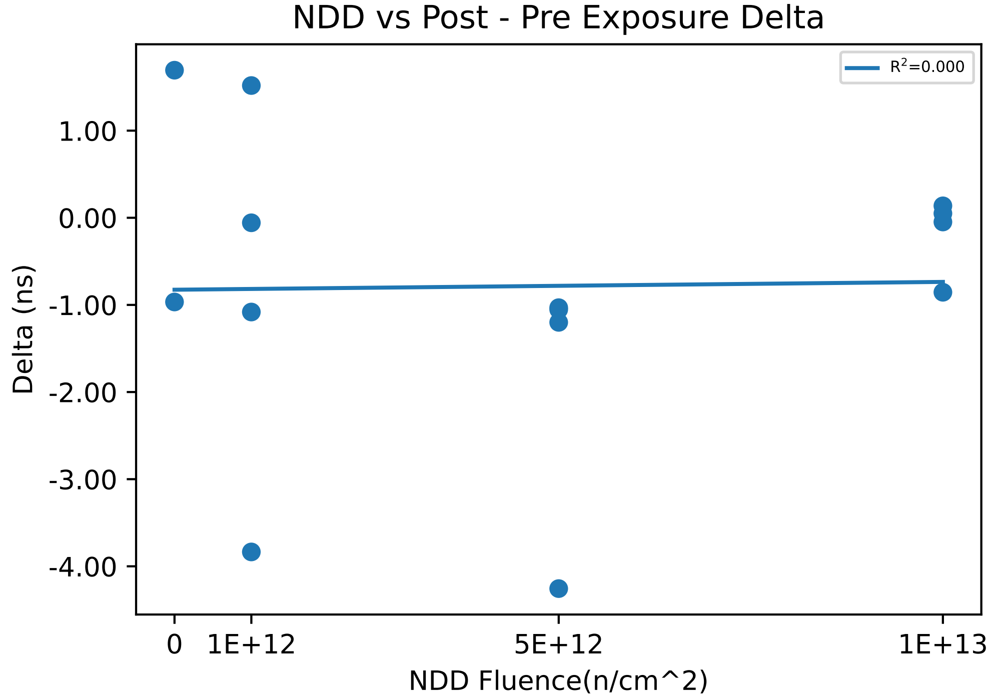
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	18.973	18.926	-0.0467
2	0	Correlation	19.672	19.159	-0.5128
30	1e+12	NDD unbiased	18.982	18.637	-0.3447
31	1e+12	NDD unbiased	19.68	17.726	-1.9538
32	1e+12	NDD unbiased	18.86	17.805	-1.0549
33	1e+12	NDD unbiased	18.339	18.373	0.0339
44	5e+12	NDD unbiased	19.458	18.494	-0.9645
45	5e+12	NDD unbiased	20.139	17.843	-2.2959
46	5e+12	NDD unbiased	20.198	19.047	-1.1511
47	5e+12	NDD unbiased	18.914	17.806	-1.1075
50	1e+13	NDD unbiased	18.291	18.452	0.1611
51	1e+13	NDD unbiased	19.466	18.568	-0.8982
52	1e+13	NDD unbiased	17.893	17.926	0.0328
53	1e+13	NDD unbiased	19.168	19.184	0.0165

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	18.973	19.322	19.672	0.4942	18.926	19.042	19.159	0.16461	-0.5128	-0.27975	-0.0467	0.32958
1e+12	18.339	18.965	19.68	0.55199	17.726	18.135	18.637	0.44165	-1.9538	-0.82988	0.0339	0.87471
5e+12	18.914	19.677	20.198	0.60969	17.806	18.297	19.047	0.59095	-2.2959	-1.3797	-0.9645	0.61594
1e+13	17.893	18.704	19.466	0.73573	17.926	18.532	19.184	0.51662	-0.8982	-0.17195	0.1611	0.48847

Device Test: 95.13 T_RLH_LARGE(_DLH Dead Time Large 2MHz VIN_10V)


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

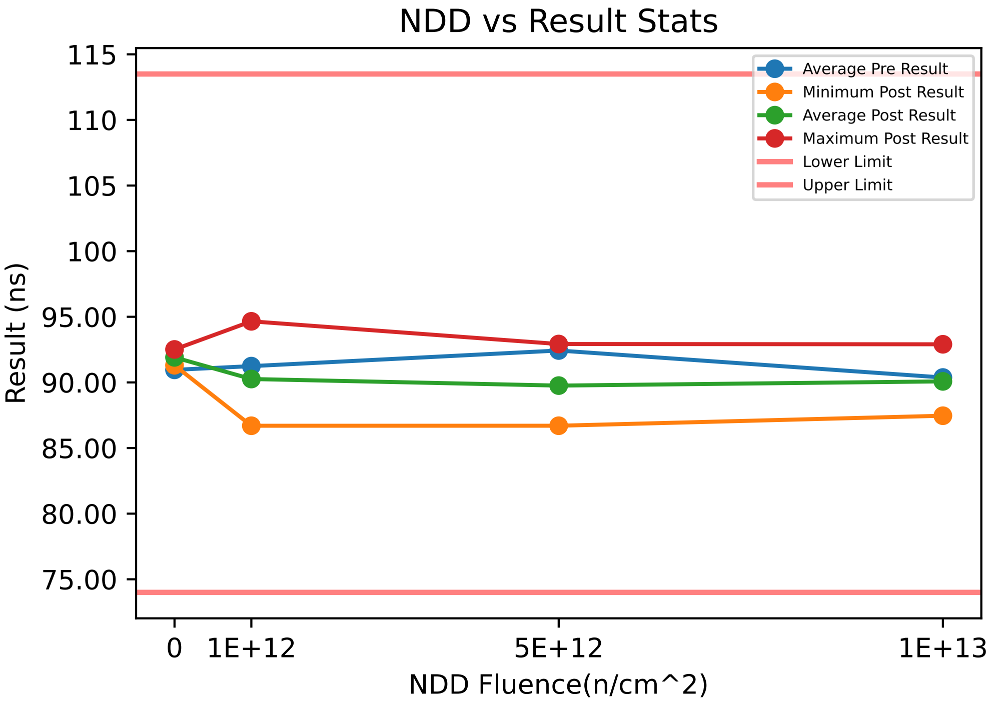
Test Results (Lower Limit = 36.0, Upper Limit = 59.0 (ns))

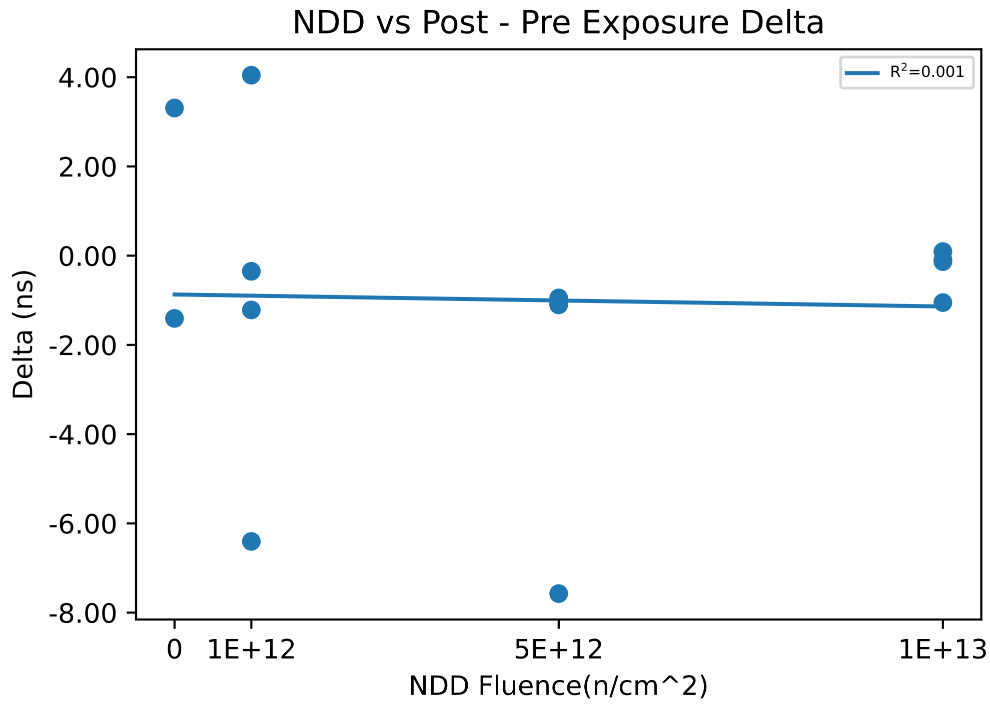
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	44.593	46.287	1.6938
2	0	Correlation	47.479	46.513	-0.9663
30	1e+12	NDD unbiased	44.747	46.265	1.5179
31	1e+12	NDD unbiased	47.526	43.691	-3.8351
32	1e+12	NDD unbiased	44.675	43.593	-1.0816
33	1e+12	NDD unbiased	46.916	46.858	-0.0574
44	5e+12	NDD unbiased	47.332	46.279	-1.053
45	5e+12	NDD unbiased	47.88	43.624	-4.2559
46	5e+12	NDD unbiased	47.727	46.696	-1.0317
47	5e+12	NDD unbiased	44.772	43.572	-1.2003
50	1e+13	NDD unbiased	45.944	45.994	0.0498
51	1e+13	NDD unbiased	45.222	44.367	-0.855
52	1e+13	NDD unbiased	43.916	44.053	0.1371
53	1e+13	NDD unbiased	46.819	46.77	-0.0483

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	44.593	46.036	47.479	2.0408	46.287	46.4	46.513	0.15981	-0.9663	0.36375	1.6938	1.881
1e+12	44.675	45.966	47.526	1.4707	43.593	45.102	46.858	1.7035	-3.8351	-0.86405	1.5179	2.2508
5e+12	44.772	46.928	47.88	1.4557	43.572	45.043	46.696	1.6768	-4.2559	-1.8852	-1.0317	1.5822
1e+13	43.916	45.475	46.819	1.2276	44.053	45.296	46.77	1.2999	-0.855	-0.1791	0.1371	0.45692

Device Test: 95.14 T_RLH_MAX(_DLH Dead Time Max 2MHz VIN_10V)





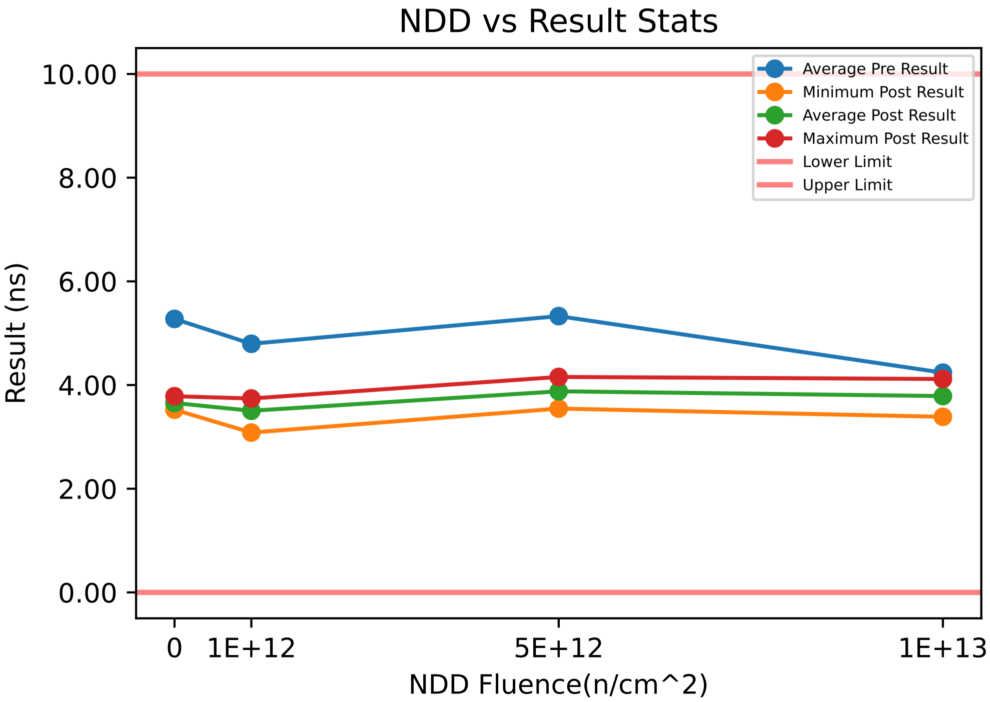
Test Results (Lower Limit = 74.0, Upper Limit = 113.5 (ns))

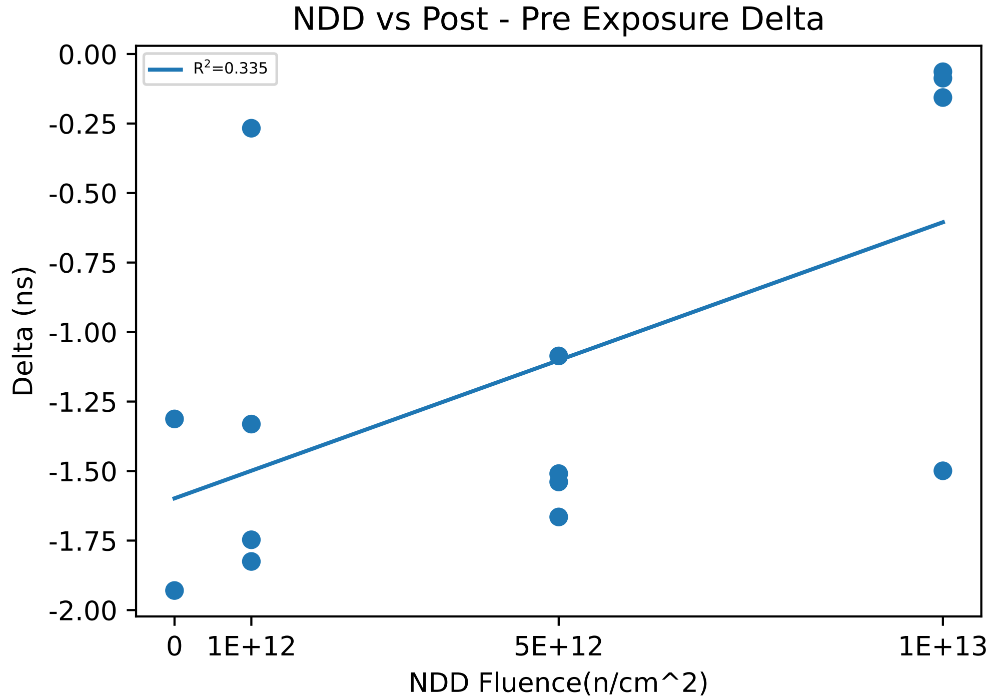
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	87.996	91.305	3.3088
2	0	Correlation	93.919	92.513	-1.4061
30	1e+12	NDD unbiased	88.445	92.49	4.0448
31	1e+12	NDD unbiased	93.597	87.193	-6.4042
32	1e+12	NDD unbiased	87.915	86.698	-1.2168
33	1e+12	NDD unbiased	95.005	94.654	-0.3501
44	5e+12	NDD unbiased	93.609	92.662	-0.9472
45	5e+12	NDD unbiased	94.273	86.699	-7.5738
46	5e+12	NDD unbiased	93.993	92.925	-1.0684
47	5e+12	NDD unbiased	87.848	86.745	-1.1032
50	1e+13	NDD unbiased	91.938	91.803	-0.1349
51	1e+13	NDD unbiased	88.513	87.462	-1.0511
52	1e+13	NDD unbiased	88.234	88.143	-0.0909
53	1e+13	NDD unbiased	92.813	92.905	0.0925

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	87.996	90.958	93.919	4.1878	91.305	91.909	92.513	0.85383	-1.4061	0.95135	3.3088	3.3339
1e+12	87.915	91.24	95.005	3.5869	86.698	90.259	94.654	3.932	-6.4042	-0.98157	4.0448	4.2865
5e+12	87.848	92.431	94.273	3.0674	86.699	89.758	92.925	3.5071	-7.5738	-2.6732	-0.9472	3.2678
1e+13	88.234	90.374	92.813	2.3407	87.462	90.078	92.905	2.6806	-1.0511	-0.2961	0.0925	0.51288

Device Test: 95.19 T_RHL_MIN(_DHL Dead Time Min 500kHz VIN_10V)





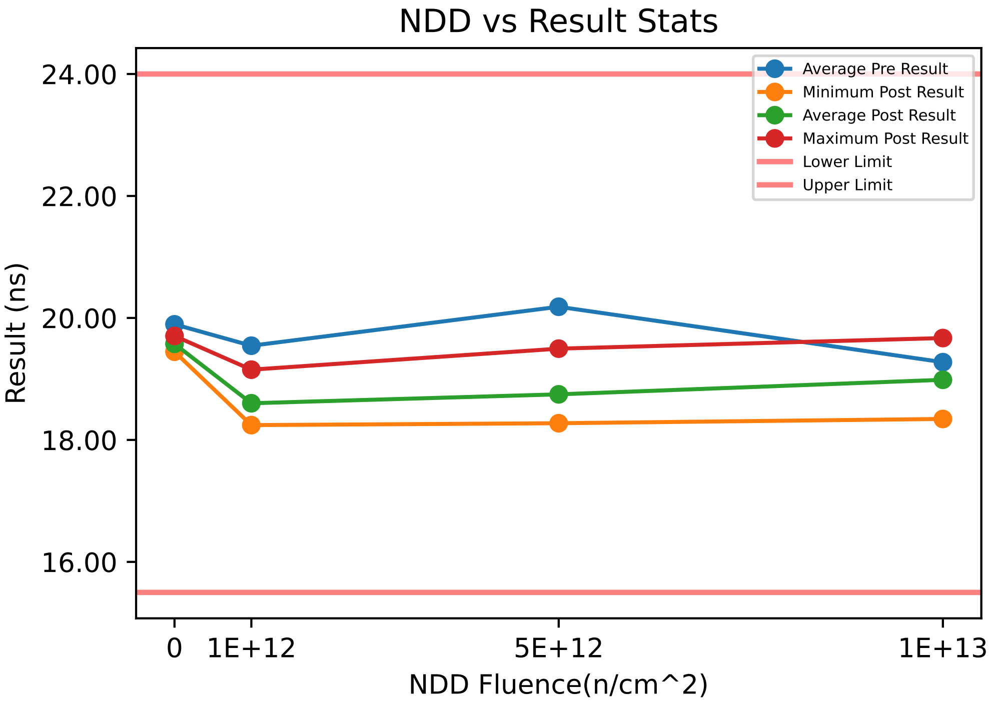
Test Results (Lower Limit = 0.0, Upper Limit = 10.0 (ns))

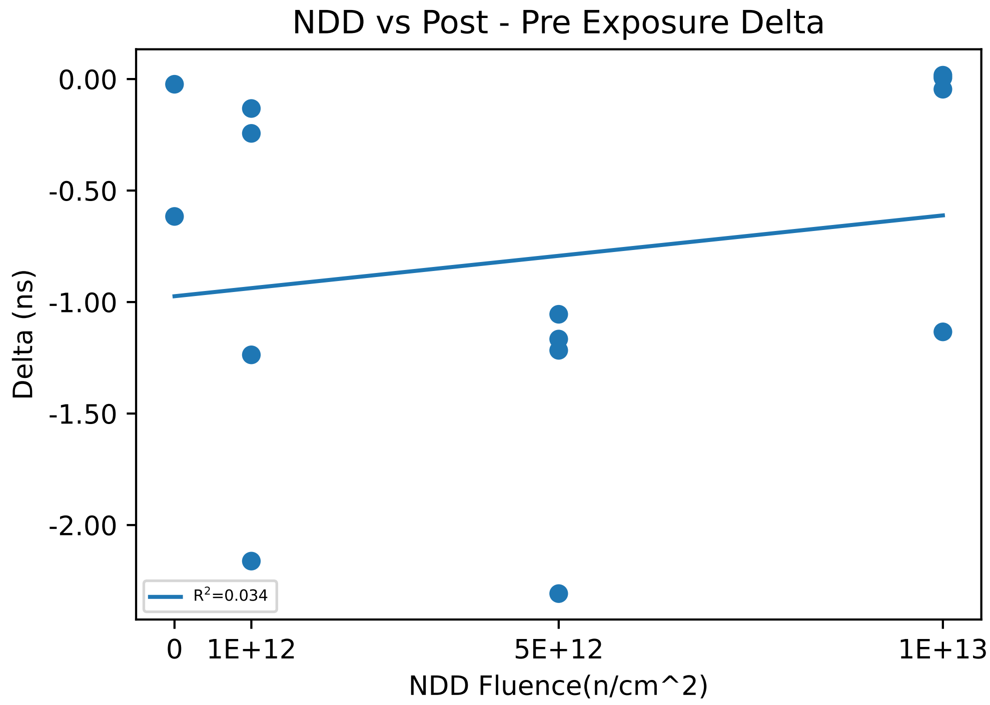
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	5.0965	3.784	-1.3125
2	0	Correlation	5.4542	3.5246	-1.9296
30	1e+12	NDD unbiased	5.34	3.5149	-1.8251
31	1e+12	NDD unbiased	5.0068	3.6758	-1.331
32	1e+12	NDD unbiased	4.8302	3.0831	-1.7471
33	1e+12	NDD unbiased	4.007	3.7401	-0.2669
44	5e+12	NDD unbiased	5.6653	4.1562	-1.5091
45	5e+12	NDD unbiased	4.9708	3.8849	-1.0859
46	5e+12	NDD unbiased	5.2112	3.5462	-1.665
47	5e+12	NDD unbiased	5.4694	3.9303	-1.5391
50	1e+13	NDD unbiased	3.451	3.3872	-0.0638
51	1e+13	NDD unbiased	5.6155	4.1165	-1.499
52	1e+13	NDD unbiased	4.0125	3.856	-0.1565
53	1e+13	NDD unbiased	3.876	3.7891	-0.0869

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.0965	5.2753	5.4542	0.25293	3.5246	3.6543	3.784	0.18342	-1.9296	-1.6211	-1.3125	0.43636
1e+12	4.007	4.796	5.34	0.56688	3.0831	3.5035	3.7401	0.29582	-1.8251	-1.2925	-0.2669	0.71732
5e+12	4.9708	5.3292	5.6653	0.30276	3.5462	3.8794	4.1562	0.25183	-1.665	-1.4498	-1.0859	0.25181
1e+13	3.451	4.2388	5.6155	0.94847	3.3872	3.7872	4.1165	0.30176	-1.499	-0.45155	-0.0638	0.69941

Device Test: 95.2 T_RLH_MID(_DLH Dead Time Mid 500kHz VIN_10V)





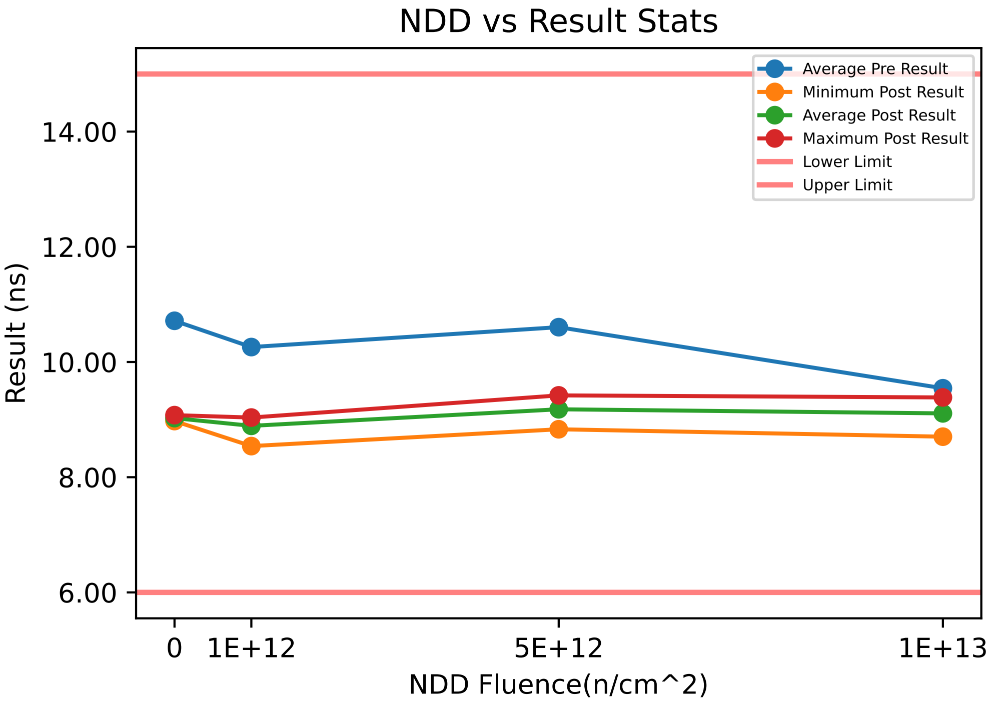
Test Results (Lower Limit = 15.5, Upper Limit = 24.0 (ns))

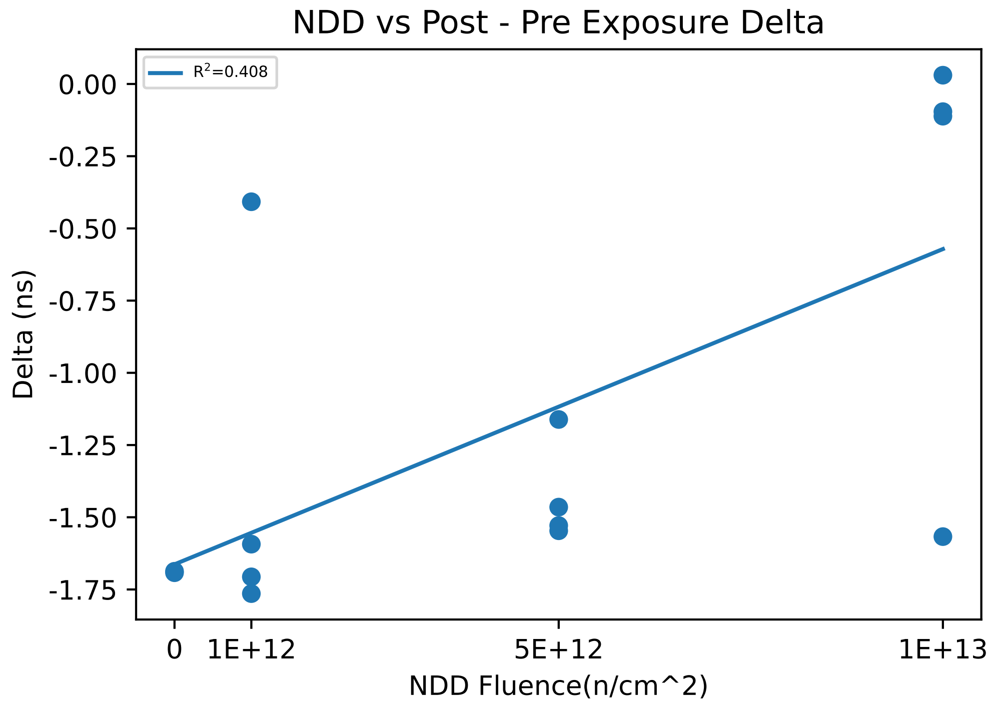
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	19.47	19.446	-0.0233
2	0	Correlation	20.321	19.705	-0.6161
30	1e+12	NDD unbiased	19.396	19.152	-0.2436
31	1e+12	NDD unbiased	20.405	18.243	-2.1617
32	1e+12	NDD unbiased	19.489	18.252	-1.2368
33	1e+12	NDD unbiased	18.89	18.758	-0.132
44	5e+12	NDD unbiased	20.103	18.937	-1.1659
45	5e+12	NDD unbiased	20.581	18.274	-2.3074
46	5e+12	NDD unbiased	20.551	19.497	-1.0548
47	5e+12	NDD unbiased	19.498	18.282	-1.2165
50	1e+13	NDD unbiased	18.897	18.903	0.0059
51	1e+13	NDD unbiased	20.16	19.026	-1.1337
52	1e+13	NDD unbiased	18.389	18.344	-0.0456
53	1e+13	NDD unbiased	19.653	19.671	0.0173

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	19.47	19.895	20.321	0.60217	19.446	19.576	19.705	0.183	-0.6161	-0.3197	-0.0233	0.41917
1e+12	18.89	19.545	20.405	0.63068	18.243	18.601	19.152	0.43894	-2.1617	-0.94353	-0.132	0.95192
5e+12	19.498	20.184	20.581	0.50648	18.274	18.747	19.497	0.58831	-2.3074	-1.4361	-1.0548	0.58475
1e+13	18.389	19.275	20.16	0.78606	18.344	18.986	19.671	0.54453	-1.1337	-0.28902	0.0173	0.56378

Device Test: 95.20 T_RHL_SMALL(_DHL Dead Time Small 500kHz VIN_10V)





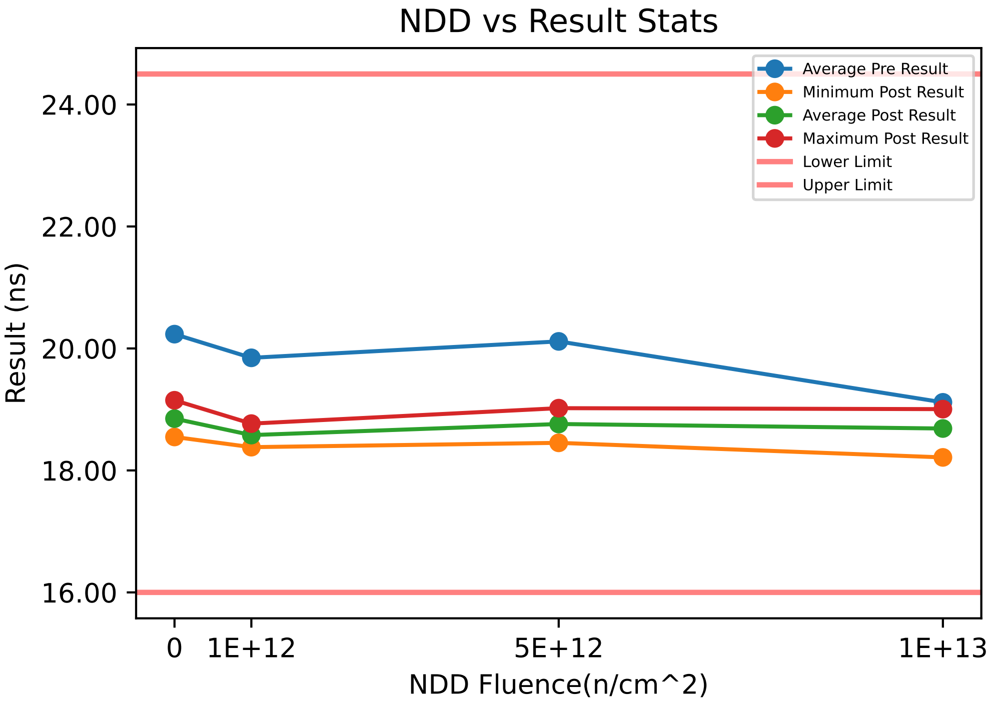
Test Results (Lower Limit = 6.0, Upper Limit = 15.0 (ns))

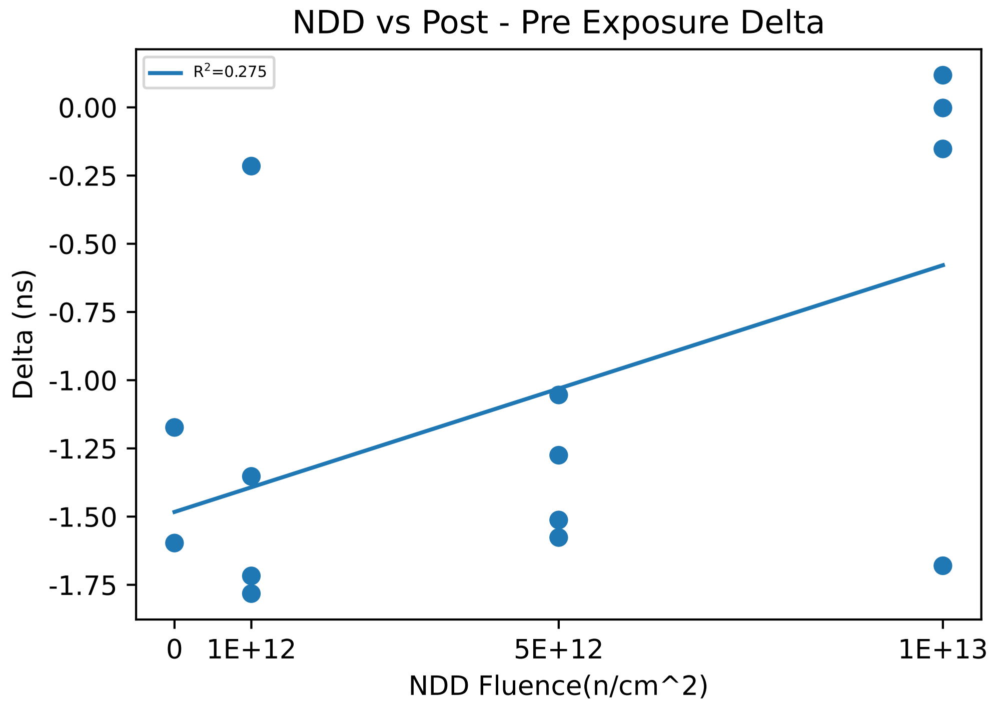
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	10.662	8.9745	-1.687
2	0	Correlation	10.769	9.0774	-1.692
30	1e+12	NDD unbiased	10.742	8.9774	-1.7643
31	1e+12	NDD unbiased	10.606	9.0131	-1.5931
32	1e+12	NDD unbiased	10.246	8.54	-1.7063
33	1e+12	NDD unbiased	9.4432	9.0355	-0.4077
44	5e+12	NDD unbiased	10.949	9.4204	-1.5288
45	5e+12	NDD unbiased	10.38	9.2189	-1.1615
46	5e+12	NDD unbiased	10.379	8.8322	-1.5467
47	5e+12	NDD unbiased	10.71	9.2451	-1.4649
50	1e+13	NDD unbiased	8.6731	8.7035	0.0304
51	1e+13	NDD unbiased	10.952	9.3849	-1.567
52	1e+13	NDD unbiased	9.3605	9.2647	-0.0958
53	1e+13	NDD unbiased	9.191	9.0795	-0.1115

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	10.662	10.715	10.769	0.076297	8.9745	9.026	9.0774	0.072761	-1.692	-1.6895	-1.687	0.0035355
1e+12	9.4432	10.259	10.742	0.58288	8.54	8.8915	9.0355	0.23555	-1.7643	-1.3678	-0.4077	0.64404
5e+12	10.379	10.605	10.949	0.27753	8.8322	9.1791	9.4204	0.248	-1.5467	-1.4255	-1.1615	0.17945
1e+13	8.6731	9.5441	10.952	0.98301	8.7035	9.1082	9.3849	0.29758	-1.567	-0.43598	0.0304	0.75669

Device Test: 95.21 T_RHL_MID(_DHL Dead Time Mid 500kHz VIN_10V)





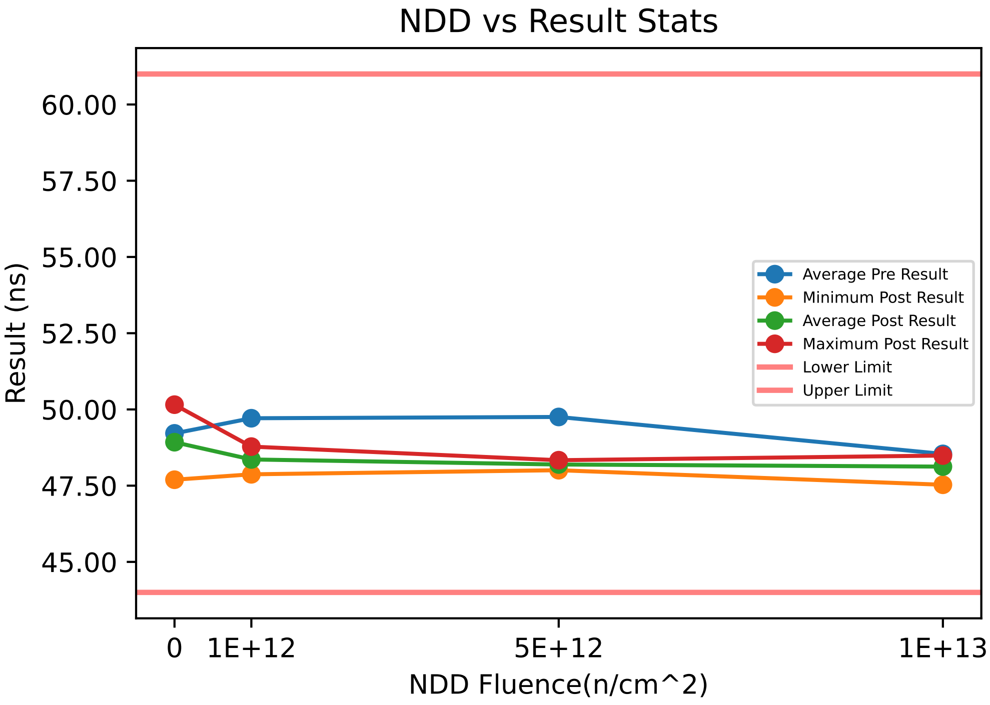
Test Results (Lower Limit = 16.0, Upper Limit = 24.5 (ns))

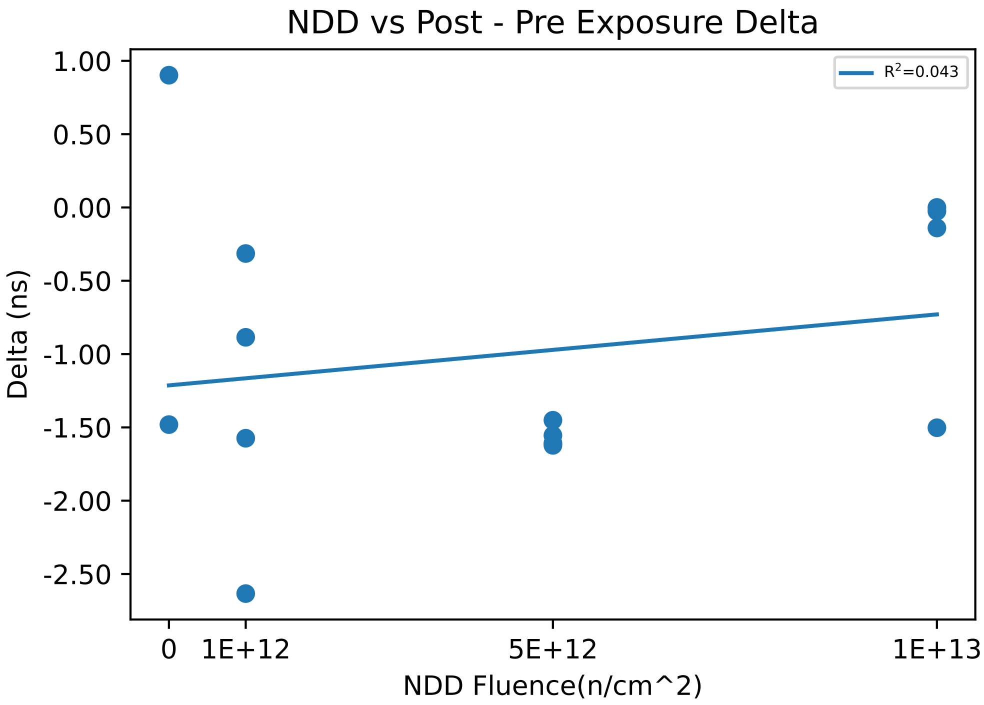
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	20.145	18.549	-1.5969
2	0	Correlation	20.323	19.15	-1.1732
30	1e+12	NDD unbiased	20.12	18.767	-1.3526
31	1e+12	NDD unbiased	20.392	18.61	-1.7822
32	1e+12	NDD unbiased	20.099	18.381	-1.7173
33	1e+12	NDD unbiased	18.774	18.559	-0.2153
44	5e+12	NDD unbiased	20.597	19.021	-1.5766
45	5e+12	NDD unbiased	19.838	18.784	-1.0541
46	5e+12	NDD unbiased	19.965	18.452	-1.5124
47	5e+12	NDD unbiased	20.062	18.787	-1.275
50	1e+13	NDD unbiased	18.096	18.213	0.1179
51	1e+13	NDD unbiased	20.685	19.005	-1.6801
52	1e+13	NDD unbiased	19.01	18.858	-0.1523
53	1e+13	NDD unbiased	18.675	18.672	-0.0022

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	20.145	20.234	20.323	0.12587	18.549	18.849	19.15	0.42547	-1.5969	-1.385	-1.1732	0.2996
1e+12	18.774	19.846	20.392	0.72688	18.381	18.579	18.767	0.15902	-1.7822	-1.2669	-0.2153	0.72609
5e+12	19.838	20.116	20.597	0.33397	18.452	18.761	19.021	0.23376	-1.5766	-1.3545	-1.0541	0.23862
1e+13	18.096	19.116	20.685	1.1119	18.213	18.687	19.005	0.34386	-1.6801	-0.42918	0.1179	0.84124

Device Test: 95.22 T_RHL_LARGE(_DHL Dead Time Large 500kHz VIN_10V)





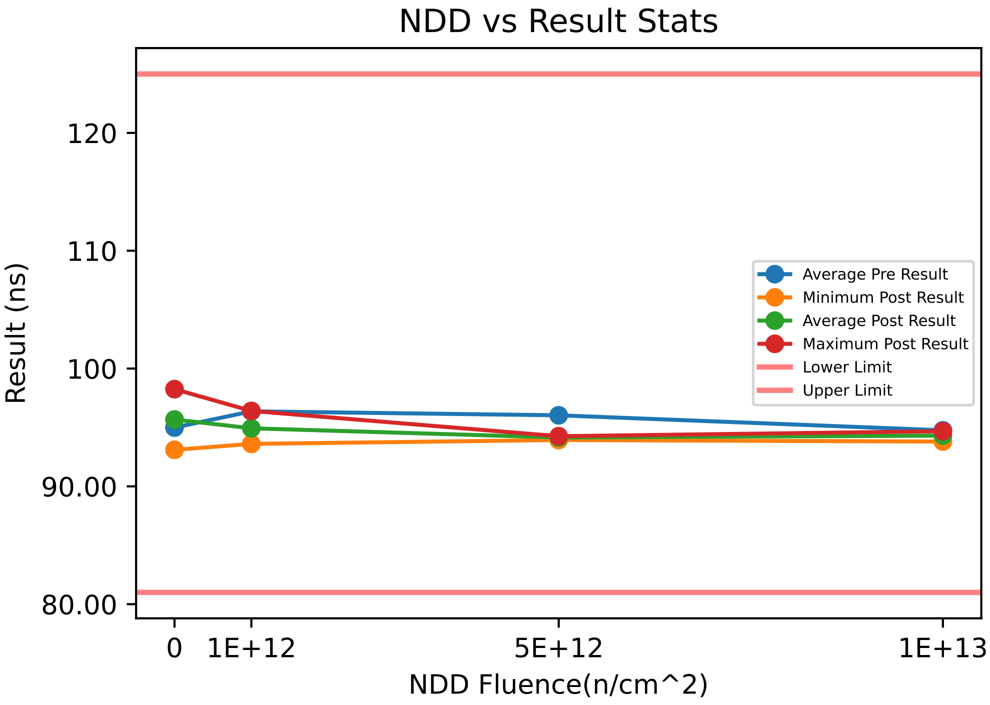
Test Results (Lower Limit = 44.0, Upper Limit = 61.0 (ns))

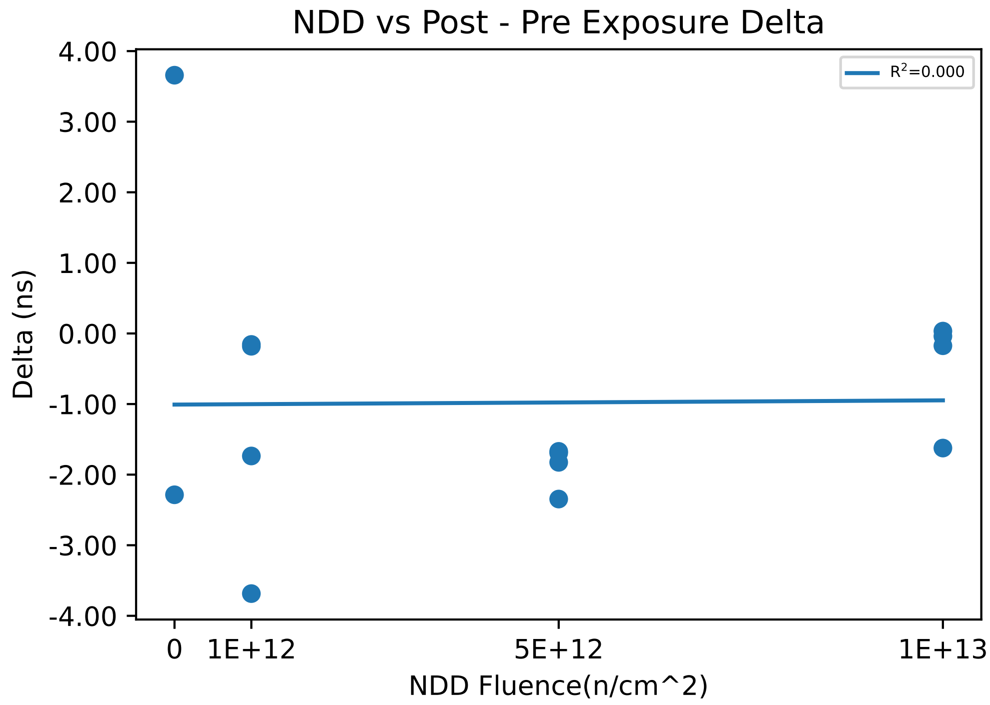
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	49.176	47.695	-1.481
2	0	Correlation	49.254	50.156	0.9021
30	1e+12	NDD unbiased	49.666	48.781	-0.8856
31	1e+12	NDD unbiased	50.709	48.075	-2.6336
32	1e+12	NDD unbiased	50.283	48.709	-1.5739
33	1e+12	NDD unbiased	48.187	47.873	-0.3141
44	5e+12	NDD unbiased	49.786	48.335	-1.4512
45	5e+12	NDD unbiased	49.807	48.2	-1.6073
46	5e+12	NDD unbiased	49.629	48.007	-1.6225
47	5e+12	NDD unbiased	49.791	48.236	-1.5549
50	1e+13	NDD unbiased	47.67	47.53	-0.1397
51	1e+13	NDD unbiased	49.99	48.487	-1.5024
52	1e+13	NDD unbiased	48.347	48.322	-0.0252
53	1e+13	NDD unbiased	48.161	48.162	0.0003

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	49.176	49.215	49.254	0.055366	47.695	48.926	50.156	1.7405	-1.481	-0.28945	0.9021	1.6851
1e+12	48.187	49.711	50.709	1.1028	47.873	48.359	48.781	0.45388	-2.6336	-1.3518	-0.3141	0.99775
5e+12	49.629	49.753	49.807	0.083083	48.007	48.194	48.335	0.13743	-1.6225	-1.559	-1.4512	0.077466
1e+13	47.67	48.542	49.99	1.0067	47.53	48.125	48.487	0.41855	-1.5024	-0.41675	0.0003	0.72632

Device Test: 95.23 T_RHL_MAX(_DHL Dead Time Max 500kHz VIN_10V)





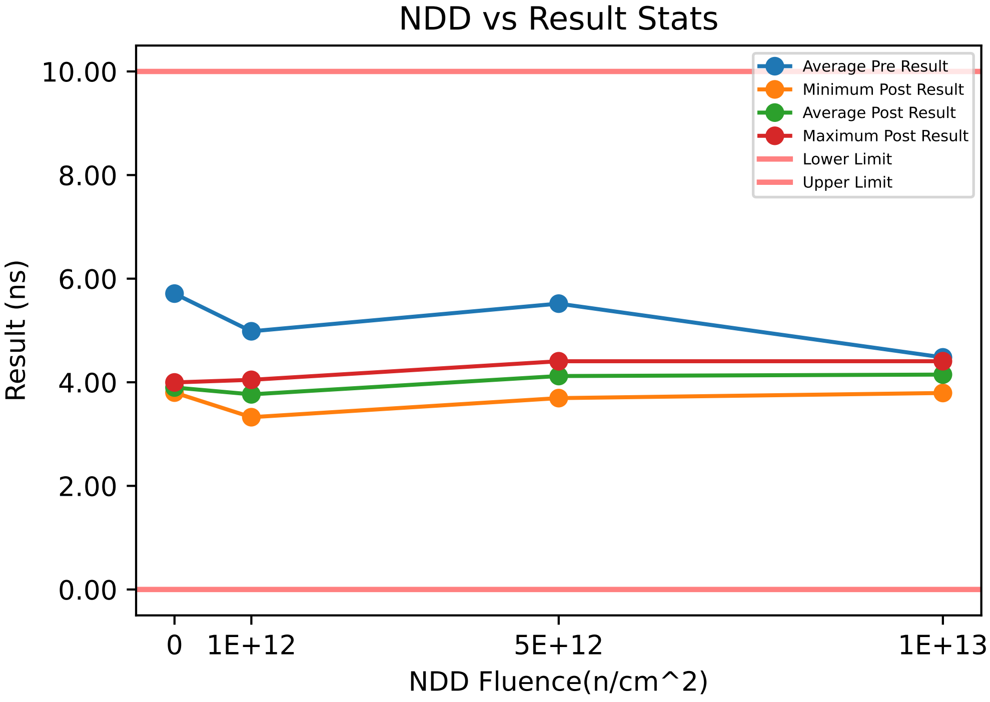
Test Results (Lower Limit = 81.0, Upper Limit = 125.0 (ns))

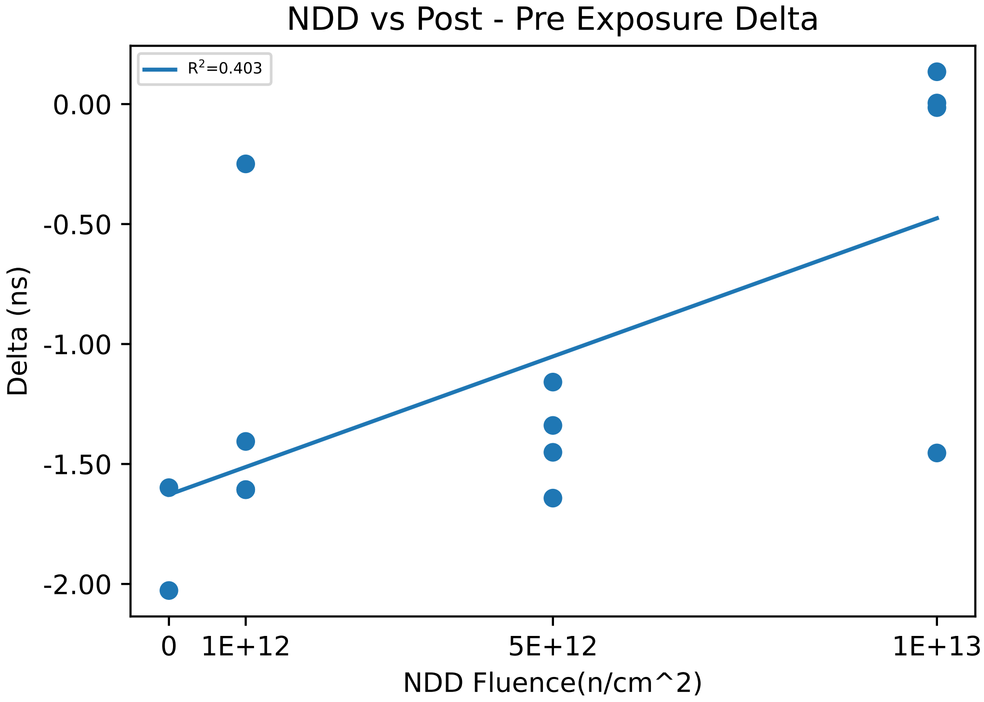
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	95.384	93.099	-2.2854
2	0	Correlation	94.593	98.251	3.6586
30	1e+12	NDD unbiased	95.732	95.577	-0.1557
31	1e+12	NDD unbiased	97.812	94.127	-3.6853
32	1e+12	NDD unbiased	98.139	96.403	-1.7357
33	1e+12	NDD unbiased	93.788	93.606	-0.1815
44	5e+12	NDD unbiased	95.602	93.932	-1.6704
45	5e+12	NDD unbiased	96.6	94.255	-2.3458
46	5e+12	NDD unbiased	95.974	94.148	-1.8259
47	5e+12	NDD unbiased	95.949	94.256	-1.693
50	1e+13	NDD unbiased	93.841	93.802	-0.0391
51	1e+13	NDD unbiased	96.178	94.554	-1.6235
52	1e+13	NDD unbiased	94.363	94.189	-0.174
53	1e+13	NDD unbiased	94.646	94.679	0.0333

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	94.593	94.988	95.384	0.55975	93.099	95.675	98.251	3.6433	-2.2854	0.6866	3.6586	4.203
1e+12	93.788	96.368	98.139	2.0234	93.606	94.928	96.403	1.289	-3.6853	-1.4396	-0.1557	1.6695
5e+12	95.602	96.031	96.6	0.41549	93.932	94.148	94.256	0.15238	-2.3458	-1.8838	-1.6704	0.31556
1e+13	93.841	94.757	96.178	1.0041	93.802	94.306	94.679	0.39511	-1.6235	-0.45082	0.0333	0.78649

Device Test: 95.24 T_RHL_MIN(_DHL Dead Time Min 1MHz VIN_10V)





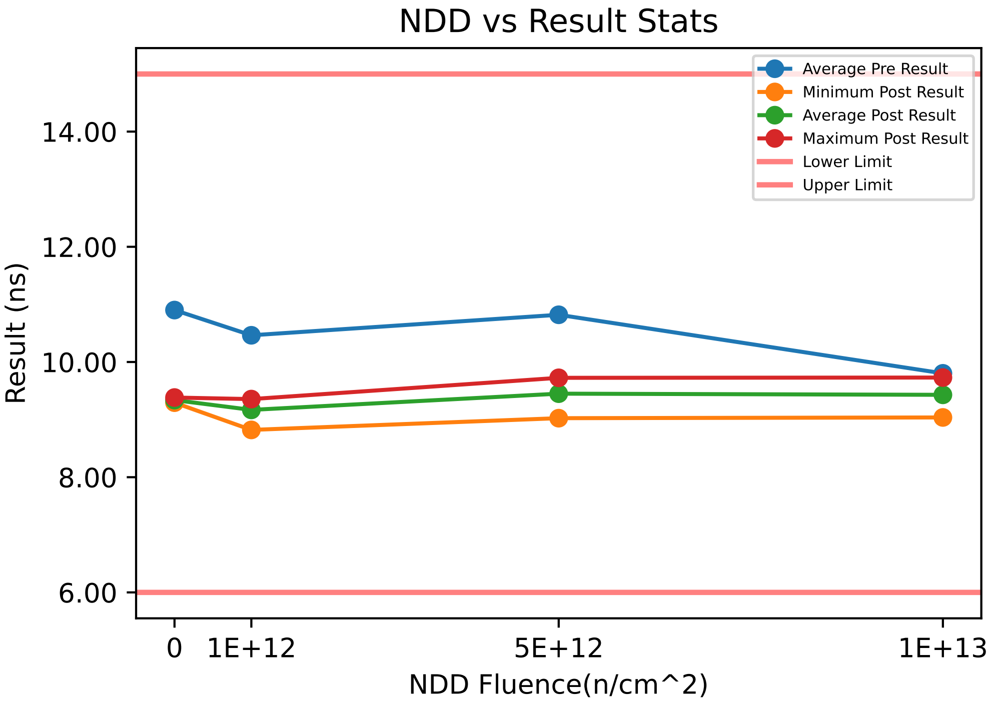
Test Results (Lower Limit = 0.0,
Upper Limit = 10.0 (ns))

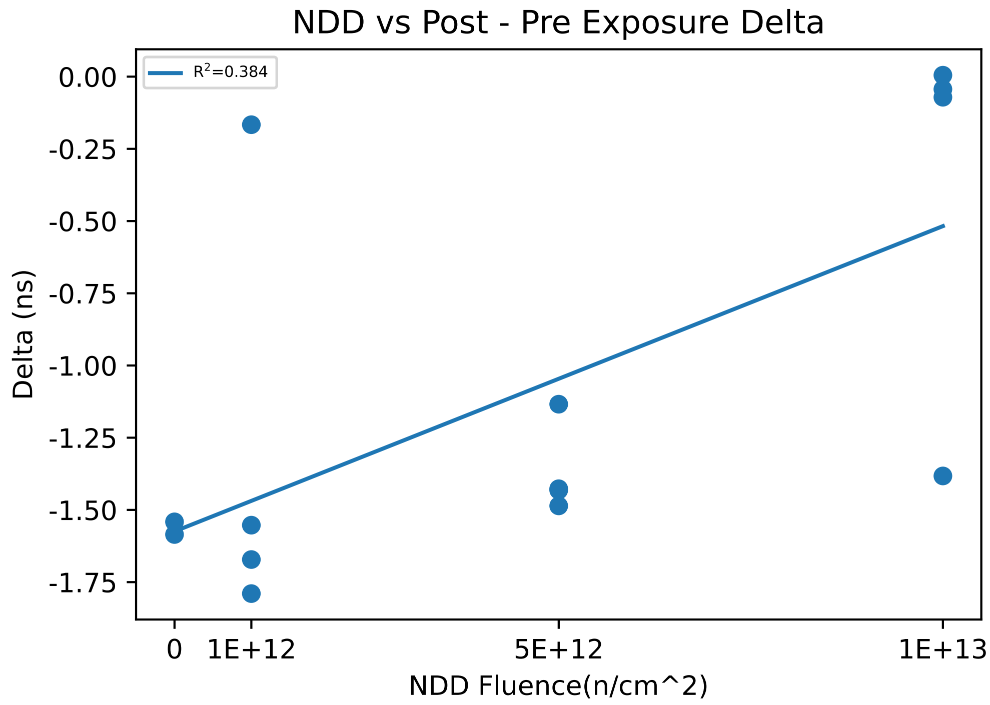
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	5.5954	3.9968	-1.5986
2	0	Correlation	5.8278	3.8005	-2.0273
30	1e+12	NDD unbiased	5.3475	3.7402	-1.6073
31	1e+12	NDD unbiased	5.3596	3.9536	-1.406
32	1e+12	NDD unbiased	4.9321	3.3256	-1.6065
33	1e+12	NDD unbiased	4.2962	4.047	-0.2492
44	5e+12	NDD unbiased	5.745	4.4057	-1.3393
45	5e+12	NDD unbiased	5.341	4.1824	-1.1586
46	5e+12	NDD unbiased	5.3362	3.694	-1.6422
47	5e+12	NDD unbiased	5.6501	4.1988	-1.4513
50	1e+13	NDD unbiased	3.6582	3.793	0.1348
51	1e+13	NDD unbiased	5.8604	4.4064	-1.454
52	1e+13	NDD unbiased	4.2757	4.2802	0.0045
53	1e+13	NDD unbiased	4.1281	4.1135	-0.0146

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.5954	5.7116	5.8278	0.16433	3.8005	3.8986	3.9968	0.13881	-2.0273	-1.8129	-1.5986	0.30314
1e+12	4.2962	4.9839	5.3596	0.49966	3.3256	3.7666	4.047	0.32082	-1.6073	-1.2173	-0.2492	0.65228
5e+12	5.3362	5.5181	5.745	0.21084	3.694	4.1202	4.4057	0.30177	-1.6422	-1.3978	-1.1586	0.20268
1e+13	3.6582	4.4806	5.8604	0.95681	3.793	4.1483	4.4064	0.26549	-1.454	-0.33232	0.1348	0.75072

Device Test: 95.25 T_RHL_SMALL(_DHL Dead Time Small 1MHz VIN_10V)





Test Results (Lower Limit = 6.0, Upper Limit = 15.0 (ns))

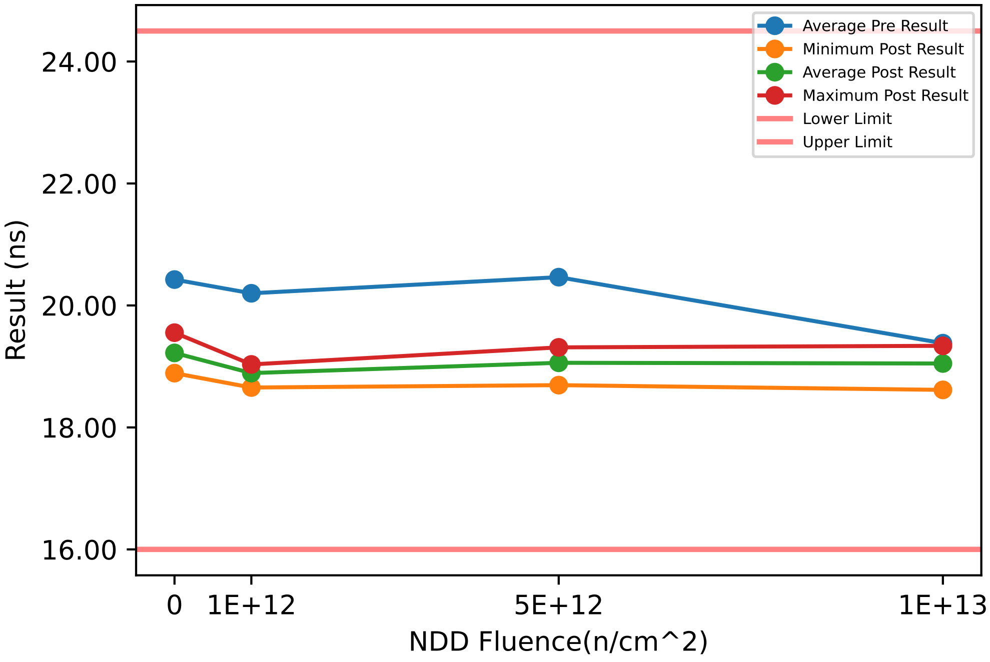
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	10.835	9.294	-1.5413
2	0	Correlation	10.968	9.383	-1.5851
30	1e+12	NDD unbiased	10.861	9.1897	-1.6718
31	1e+12	NDD unbiased	10.86	9.3075	-1.5528
32	1e+12	NDD unbiased	10.611	8.8211	-1.7897
33	1e+12	NDD unbiased	9.5224	9.356	-0.1664
44	5e+12	NDD unbiased	11.157	9.7253	-1.4316
45	5e+12	NDD unbiased	10.637	9.5033	-1.134
46	5e+12	NDD unbiased	10.511	9.0246	-1.486
47	5e+12	NDD unbiased	10.974	9.5477	-1.4267
50	1e+13	NDD unbiased	9.0809	9.0374	-0.0435
51	1e+13	NDD unbiased	11.112	9.73	-1.3824
52	1e+13	NDD unbiased	9.5984	9.6034	0.005
53	1e+13	NDD unbiased	9.421	9.3497	-0.0713

Test Statistics (ns)

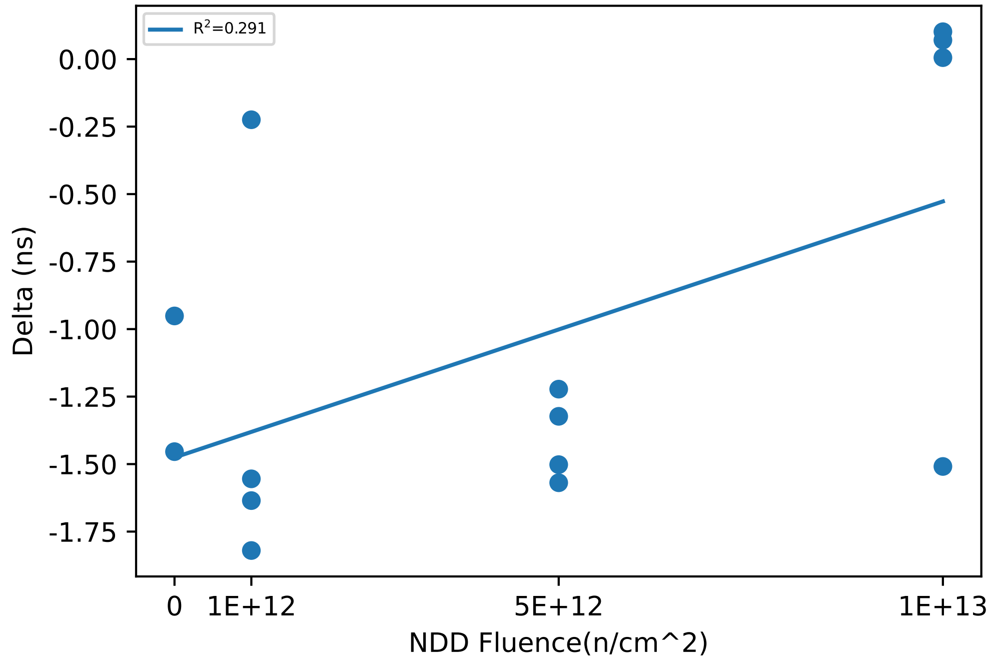
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	10.835	10.902	10.968	0.093904	9.294	9.3385	9.383	0.062933	-1.5851	-1.5632	-1.5413	0.030971
1e+12	9.5224	10.464	10.861	0.63855	8.8211	9.1686	9.356	0.24195	-1.7897	-1.2952	-0.1664	0.75871
5e+12	10.511	10.82	11.157	0.29802	9.0246	9.4502	9.7253	0.29952	-1.486	-1.3696	-1.134	0.15933
1e+13	9.0809	9.8032	11.112	0.89884	9.0374	9.4301	9.73	0.30586	-1.3824	-0.37305	0.005	0.67364

Device Test: 95.26 T_RHL_MID(_DHL Dead Time Mid 1MHz VIN_10V)

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



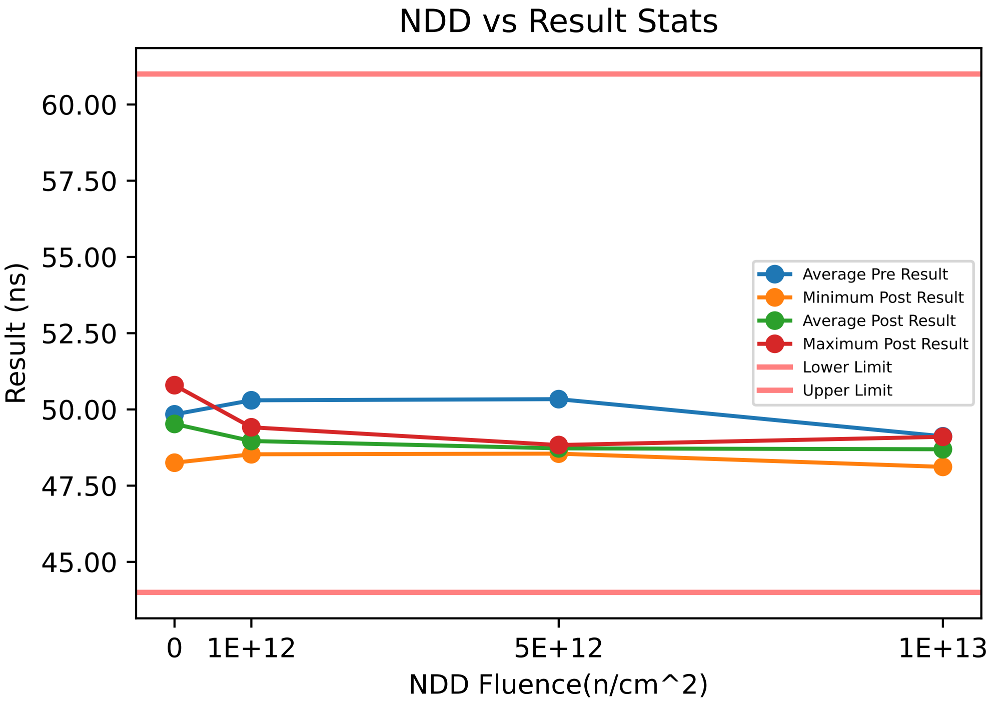
Test Results (Lower Limit = 16.0, Upper Limit = 24.5 (ns))

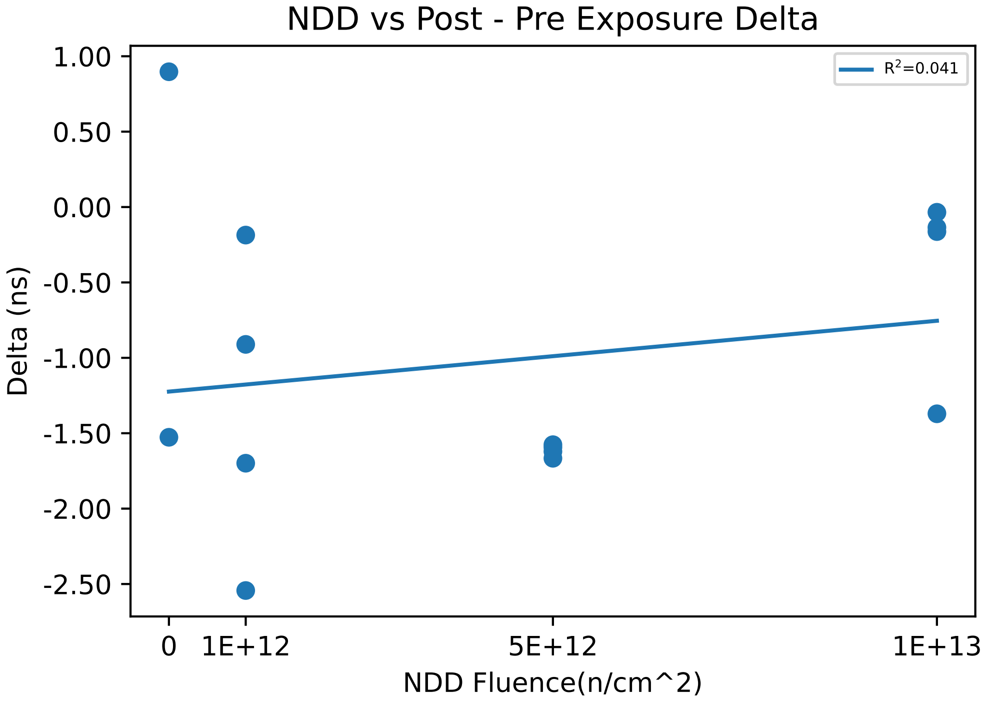
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	20.344	18.89	-1.4539
2	0	Correlation	20.505	19.554	-0.9513
30	1e+12	NDD unbiased	20.668	19.033	-1.6352
31	1e+12	NDD unbiased	20.714	18.893	-1.8201
32	1e+12	NDD unbiased	20.209	18.654	-1.5546
33	1e+12	NDD unbiased	19.207	18.983	-0.2246
44	5e+12	NDD unbiased	20.815	19.313	-1.502
45	5e+12	NDD unbiased	20.325	19.102	-1.2224
46	5e+12	NDD unbiased	20.262	18.693	-1.5691
47	5e+12	NDD unbiased	20.453	19.13	-1.3231
50	1e+13	NDD unbiased	18.514	18.616	0.1014
51	1e+13	NDD unbiased	20.847	19.338	-1.5088
52	1e+13	NDD unbiased	19.243	19.248	0.0054
53	1e+13	NDD unbiased	18.922	18.992	0.0702

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	20.344	20.424	20.505	0.11384	18.89	19.222	19.554	0.46924	-1.4539	-1.2026	-0.9513	0.35539
1e+12	19.207	20.199	20.714	0.6997	18.654	18.891	19.033	0.16792	-1.8201	-1.3086	-0.2246	0.73118
5e+12	20.262	20.464	20.815	0.247	18.693	19.06	19.313	0.2614	-1.5691	-1.4041	-1.2224	0.15957
1e+13	18.514	19.381	20.847	1.0215	18.616	19.048	19.338	0.32366	-1.5088	-0.33295	0.1014	0.78492

Device Test: 95.27 T_RHL_LARGE(_DHL Dead Time Large 1MHz VIN_10V)





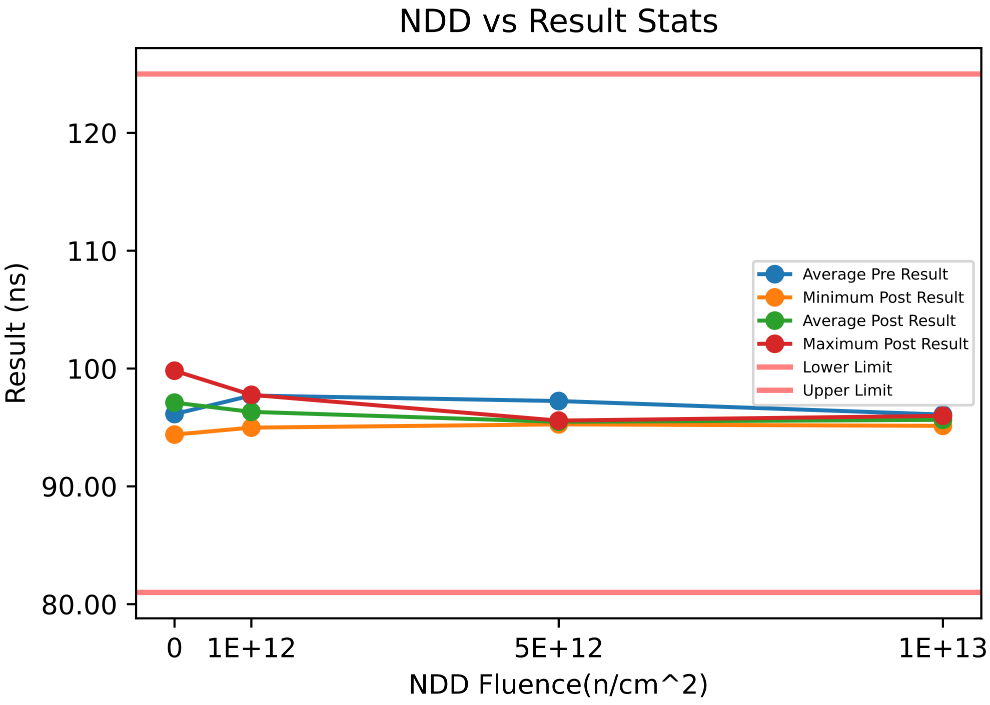
Test Results (Lower Limit = 44.0,
Upper Limit = 61.0 (ns))

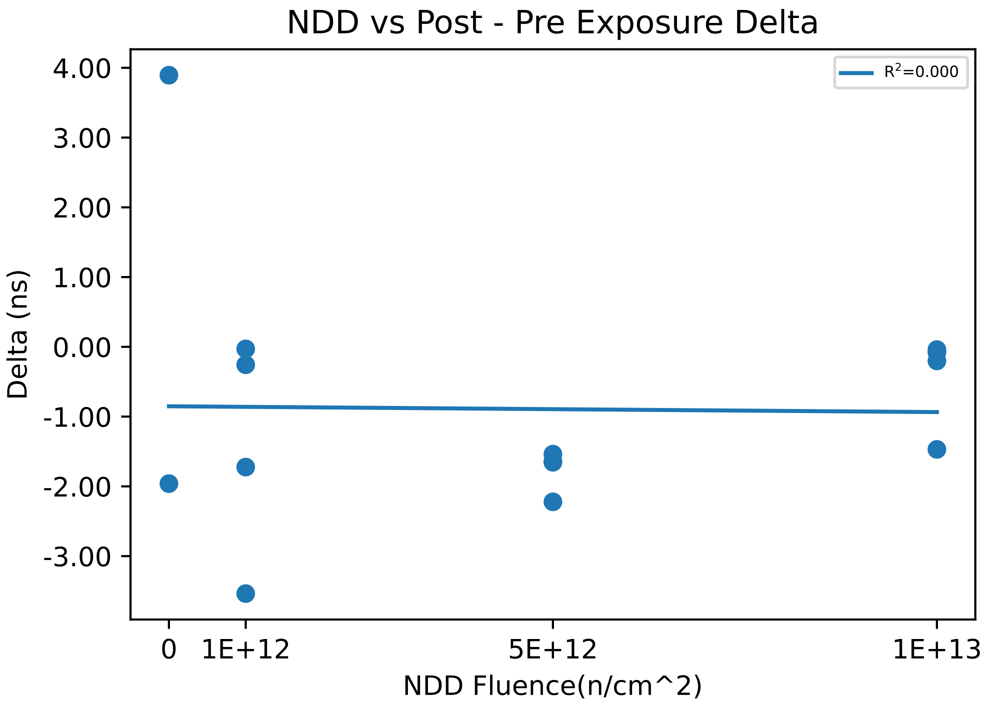
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	49.78	48.253	-1.5269
2	0	Correlation	49.898	50.796	0.8972
30	1e+12	NDD unbiased	50.325	49.414	-0.9109
31	1e+12	NDD unbiased	51.19	48.647	-2.5431
32	1e+12	NDD unbiased	50.968	49.269	-1.6989
33	1e+12	NDD unbiased	48.716	48.53	-0.1859
44	5e+12	NDD unbiased	50.499	48.833	-1.6661
45	5e+12	NDD unbiased	50.364	48.743	-1.621
46	5e+12	NDD unbiased	50.144	48.55	-1.5939
47	5e+12	NDD unbiased	50.342	48.766	-1.576
50	1e+13	NDD unbiased	48.252	48.116	-0.1354
51	1e+13	NDD unbiased	50.474	49.102	-1.3711
52	1e+13	NDD unbiased	48.928	48.894	-0.0347
53	1e+13	NDD unbiased	48.826	48.664	-0.1627

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	49.78	49.839	49.898	0.083934	48.253	49.524	50.796	1.798	-1.5269	-0.31485	0.8972	1.7141
1e+12	48.716	50.3	51.19	1.118	48.53	48.965	49.414	0.44137	-2.5431	-1.3347	-0.1859	1.0153
5e+12	50.144	50.337	50.499	0.14617	48.55	48.723	48.833	0.12126	-1.6661	-1.6143	-1.576	0.039205
1e+13	48.252	49.12	50.474	0.95028	48.116	48.694	49.102	0.42482	-1.3711	-0.42597	-0.0347	0.63248

Device Test: 95.28 T_RHL_MAX(_DHL Dead Time Max 1MHz VIN_10V)


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

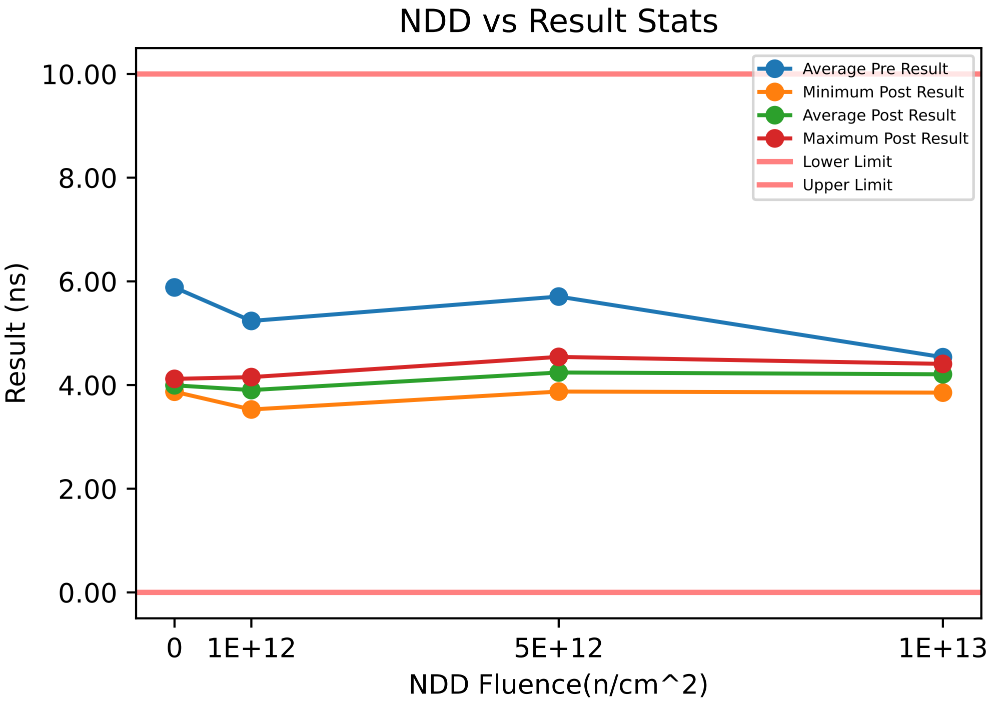
Test Results (Lower Limit = 81.0, Upper Limit = 125.0 (ns))

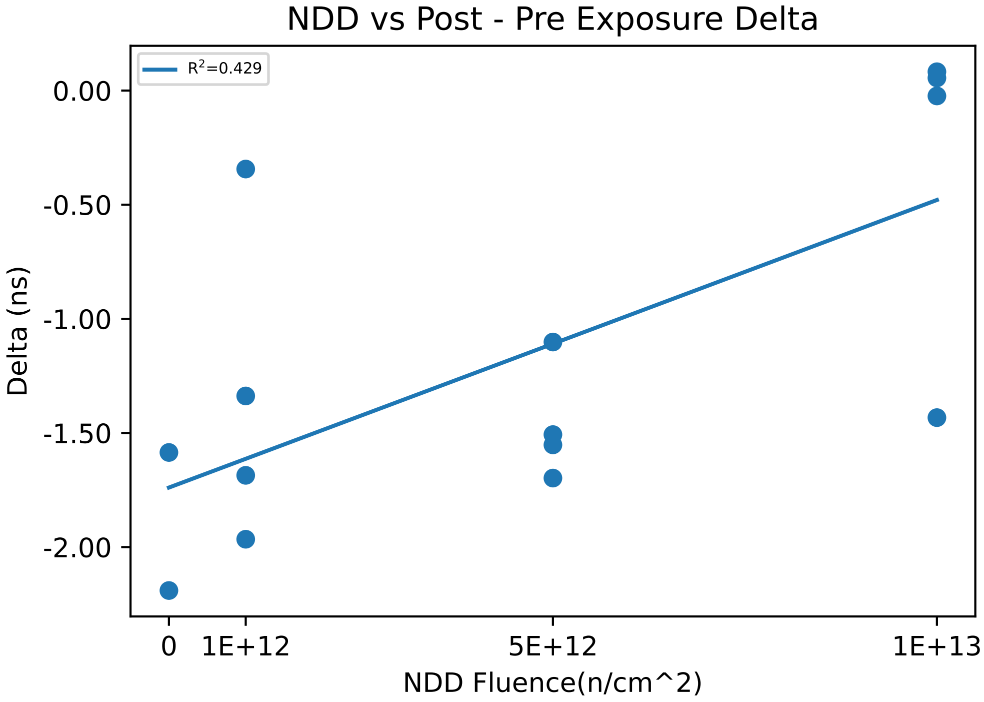
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	96.357	94.397	-1.9605
2	0	Correlation	95.921	99.815	3.8941
30	1e+12	NDD unbiased	97.125	97.096	-0.0293
31	1e+12	NDD unbiased	98.98	95.443	-3.5372
32	1e+12	NDD unbiased	99.493	97.769	-1.7237
33	1e+12	NDD unbiased	95.242	94.985	-0.2571
44	5e+12	NDD unbiased	96.917	95.262	-1.6546
45	5e+12	NDD unbiased	97.75	95.528	-2.2219
46	5e+12	NDD unbiased	97.186	95.545	-1.6403
47	5e+12	NDD unbiased	97.12	95.582	-1.5381
50	1e+13	NDD unbiased	95.176	95.136	-0.0397
51	1e+13	NDD unbiased	97.331	95.861	-1.4697
52	1e+13	NDD unbiased	95.802	95.6	-0.2019
53	1e+13	NDD unbiased	96.062	95.984	-0.0775

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	95.921	96.139	96.357	0.30872	94.397	97.106	99.815	3.8311	-1.9605	0.9668	3.8941	4.1398
1e+12	95.242	97.71	99.493	1.9344	94.985	96.323	97.769	1.3233	-3.5372	-1.3868	-0.0293	1.6183
5e+12	96.917	97.243	97.75	0.35654	95.262	95.479	95.582	0.14658	-2.2219	-1.7637	-1.5381	0.30982
1e+13	95.176	96.093	97.331	0.90529	95.136	95.645	95.984	0.37535	-1.4697	-0.4472	-0.0397	0.68518

Device Test: 95.29 T_RHL_MIN(_DHL Dead Time Min 2MHz VIN_10V)





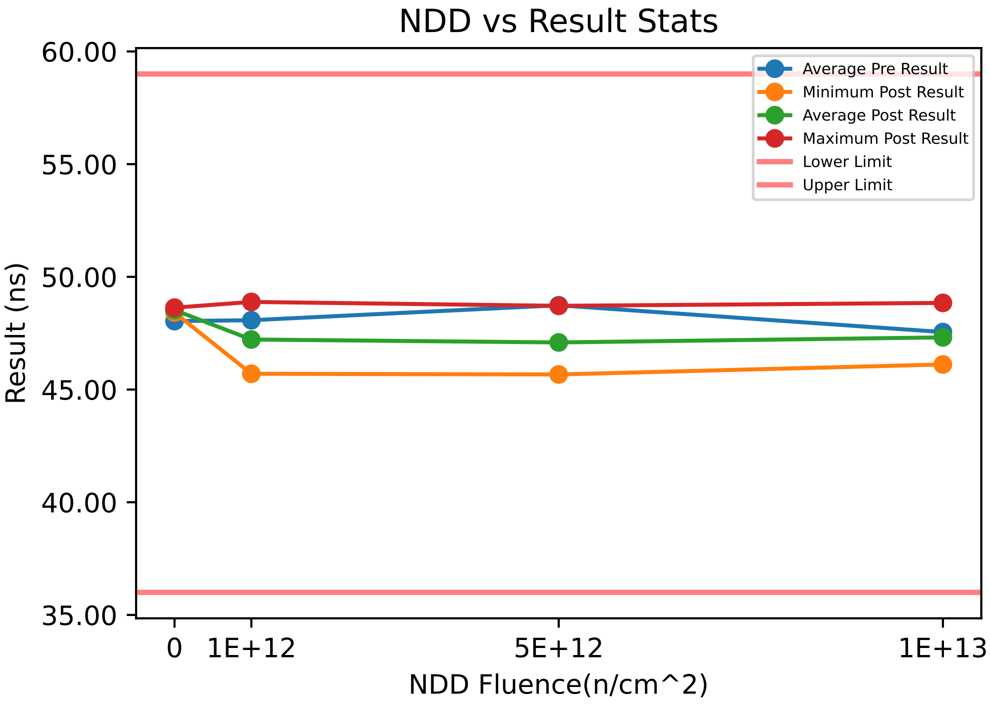
Test Results (Lower Limit = 0.0, Upper Limit = 10.0 (ns))

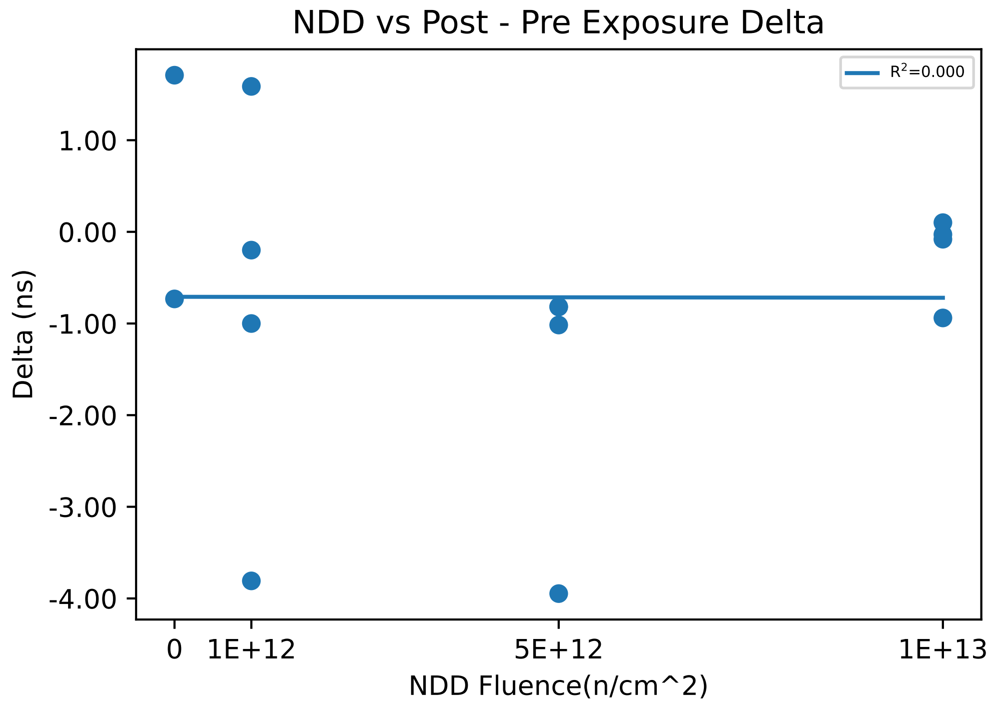
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	5.7042	4.1187	-1.5855
2	0	Correlation	6.0611	3.8708	-2.1903
30	1e+12	NDD unbiased	5.8053	3.8397	-1.9656
31	1e+12	NDD unbiased	5.4294	4.0914	-1.338
32	1e+12	NDD unbiased	5.2139	3.5282	-1.6857
33	1e+12	NDD unbiased	4.4969	4.1531	-0.3438
44	5e+12	NDD unbiased	6.0951	4.5428	-1.5523
45	5e+12	NDD unbiased	5.4058	4.3041	-1.1017
46	5e+12	NDD unbiased	5.572	3.8743	-1.6977
47	5e+12	NDD unbiased	5.7537	4.2465	-1.5072
50	1e+13	NDD unbiased	3.7708	3.8532	0.0824
51	1e+13	NDD unbiased	5.8408	4.4079	-1.4329
52	1e+13	NDD unbiased	4.3051	4.3605	0.0554
53	1e+13	NDD unbiased	4.2317	4.2081	-0.0236

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.7042	5.8826	6.0611	0.25237	3.8708	3.9947	4.1187	0.17529	-2.1903	-1.8879	-1.5855	0.42766
1e+12	4.4969	5.2364	5.8053	0.55023	3.5282	3.9031	4.1531	0.28433	-1.9656	-1.3333	-0.3438	0.70784
5e+12	5.4058	5.7066	6.0951	0.29538	3.8743	4.2419	4.5428	0.27662	-1.6977	-1.4647	-1.1017	0.2553
1e+13	3.7708	4.5371	5.8408	0.90073	3.8532	4.2074	4.4079	0.25106	-1.4329	-0.32968	0.0824	0.73686

Device Test: 95.3 T_RLH_LARGE(_DLH Dead Time Large 500kHz VIN_10V)


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

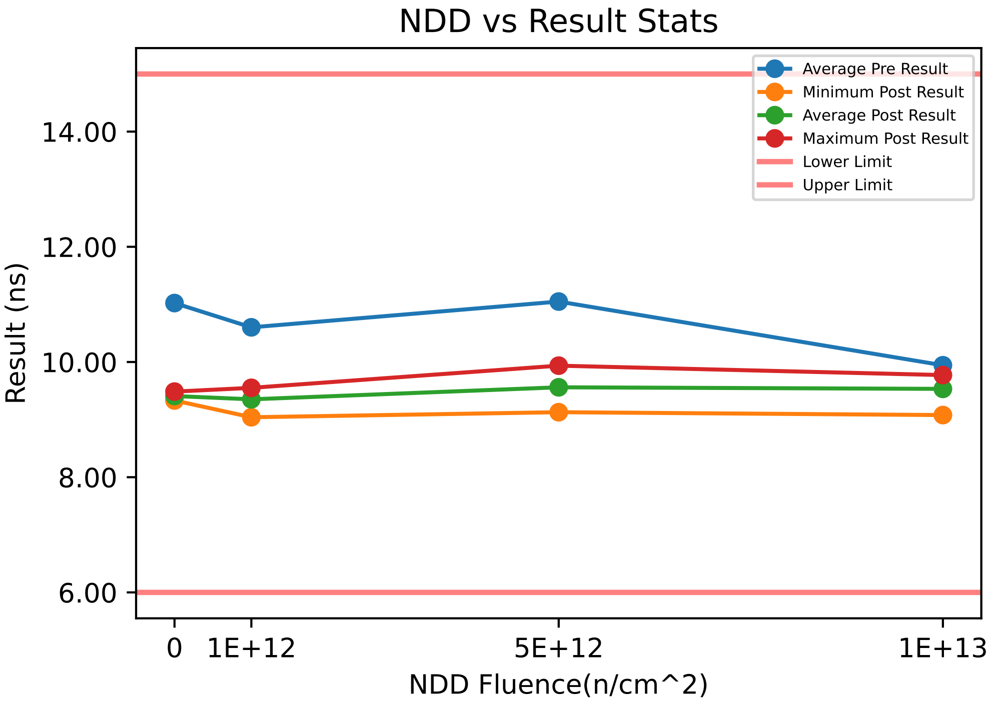
Test Results (Lower Limit = 36.0, Upper Limit = 59.0 (ns))

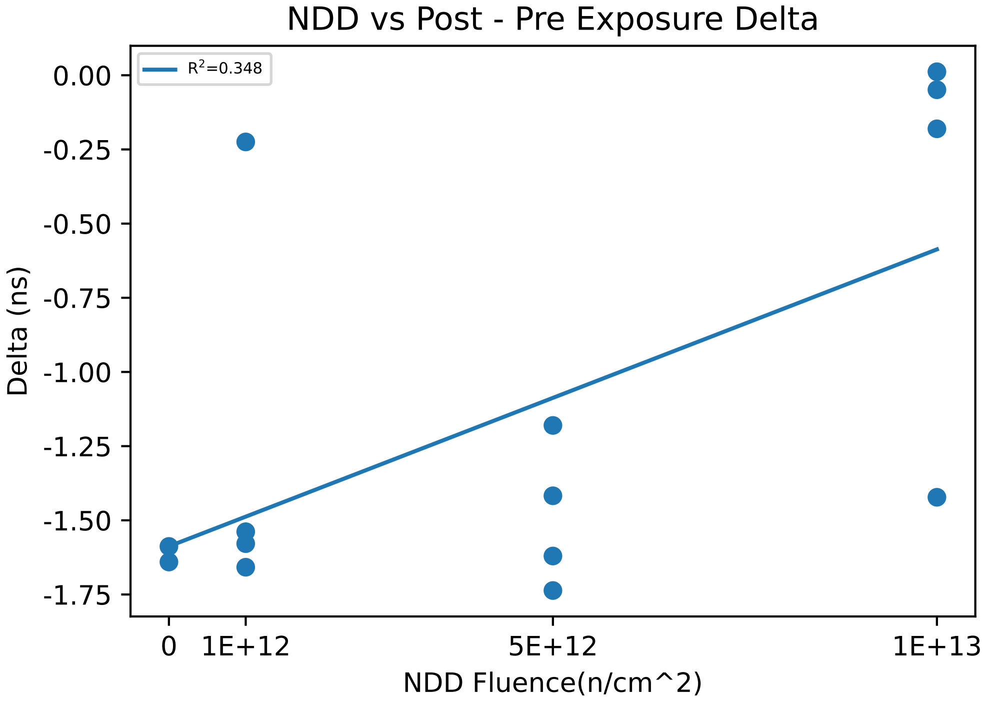
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	46.708	48.418	1.7093
2	0	Correlation	49.365	48.633	-0.7318
30	1e+12	NDD unbiased	46.893	48.48	1.587
31	1e+12	NDD unbiased	49.621	45.813	-3.8085
32	1e+12	NDD unbiased	46.701	45.701	-1.0002
33	1e+12	NDD unbiased	49.087	48.888	-0.1994
44	5e+12	NDD unbiased	49.068	48.252	-0.8157
45	5e+12	NDD unbiased	49.67	45.723	-3.9472
46	5e+12	NDD unbiased	49.534	48.714	-0.8196
47	5e+12	NDD unbiased	46.686	45.669	-1.0166
50	1e+13	NDD unbiased	48.05	47.97	-0.0805
51	1e+13	NDD unbiased	47.267	46.328	-0.9393
52	1e+13	NDD unbiased	46.142	46.114	-0.0287
53	1e+13	NDD unbiased	48.744	48.844	0.1005

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	46.708	48.037	49.365	1.8785	48.418	48.525	48.633	0.15238	-0.7318	0.48875	1.7093	1.7261
1e+12	46.701	48.075	49.621	1.4945	45.701	47.22	48.888	1.6987	-3.8085	-0.85527	1.587	2.2463
5e+12	46.686	48.739	49.67	1.3932	45.669	47.09	48.714	1.6204	-3.9472	-1.6498	-0.8157	1.5345
1e+13	46.142	47.551	48.744	1.116	46.114	47.314	48.844	1.3147	-0.9393	-0.237	0.1005	0.47435

Device Test: 95.30 T_RHL_SMALL(_DHL Dead Time Small 2MHz VIN_10V)





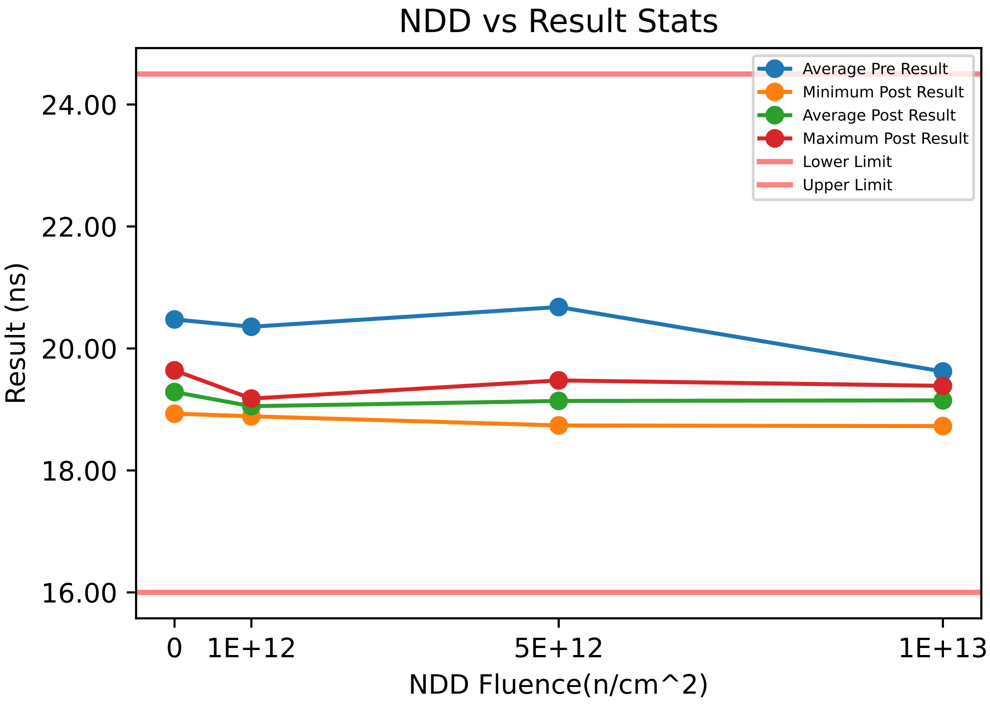
Test Results (Lower Limit = 6.0, Upper Limit = 15.0 (ns))

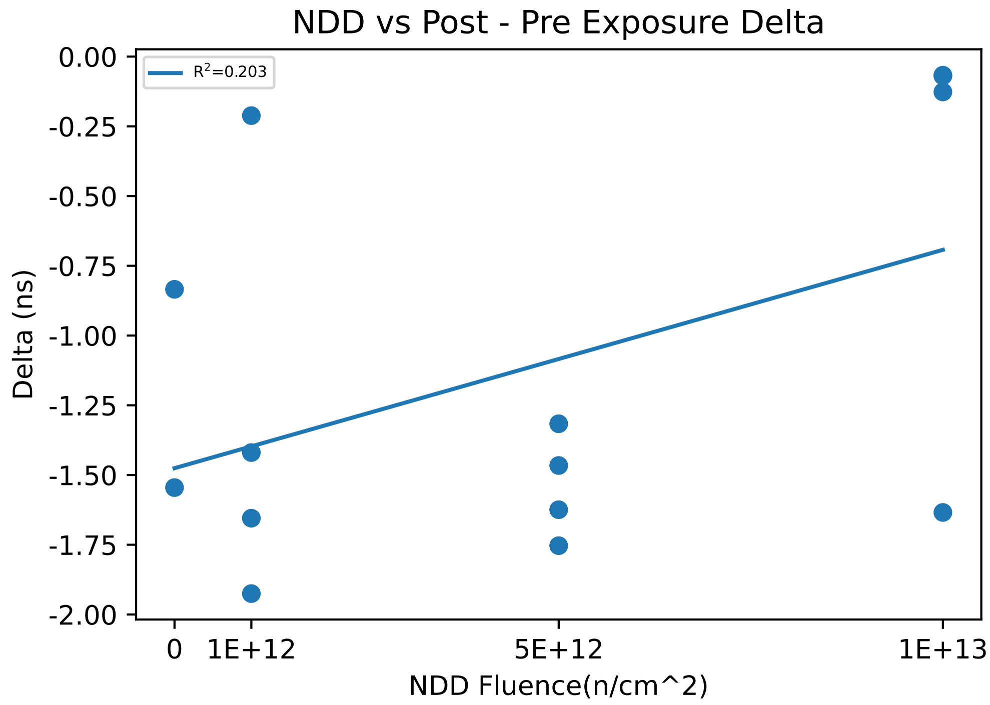
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	10.92	9.3322	-1.588
2	0	Correlation	11.126	9.4859	-1.6405
30	1e+12	NDD unbiased	11.018	9.3604	-1.6581
31	1e+12	NDD unbiased	11.034	9.4552	-1.5786
32	1e+12	NDD unbiased	10.579	9.0409	-1.5384
33	1e+12	NDD unbiased	9.7761	9.5514	-0.2247
44	5e+12	NDD unbiased	11.354	9.9363	-1.4173
45	5e+12	NDD unbiased	10.726	9.5463	-1.1802
46	5e+12	NDD unbiased	10.865	9.1284	-1.7366
47	5e+12	NDD unbiased	11.252	9.6318	-1.6203
50	1e+13	NDD unbiased	9.2591	9.0786	-0.1805
51	1e+13	NDD unbiased	11.195	9.773	-1.4223
52	1e+13	NDD unbiased	9.7505	9.7623	0.0118
53	1e+13	NDD unbiased	9.5687	9.5198	-0.0489

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	10.92	11.023	11.126	0.14581	9.3322	9.4091	9.4859	0.10868	-1.6405	-1.6142	-1.588	0.037123
1e+12	9.7761	10.602	11.034	0.58951	9.0409	9.352	9.5514	0.22156	-1.6581	-1.2499	-0.2247	0.68531
5e+12	10.726	11.049	11.354	0.30105	9.1284	9.5607	9.9363	0.33328	-1.7366	-1.4886	-1.1802	0.2443
1e+13	9.2591	9.9434	11.195	0.8589	9.0786	9.5334	9.773	0.32498	-1.4223	-0.40998	0.0118	0.67964

Device Test: 95.31 T_RHL_MID(_DHL Dead Time Mid 2MHz VIN_10V)





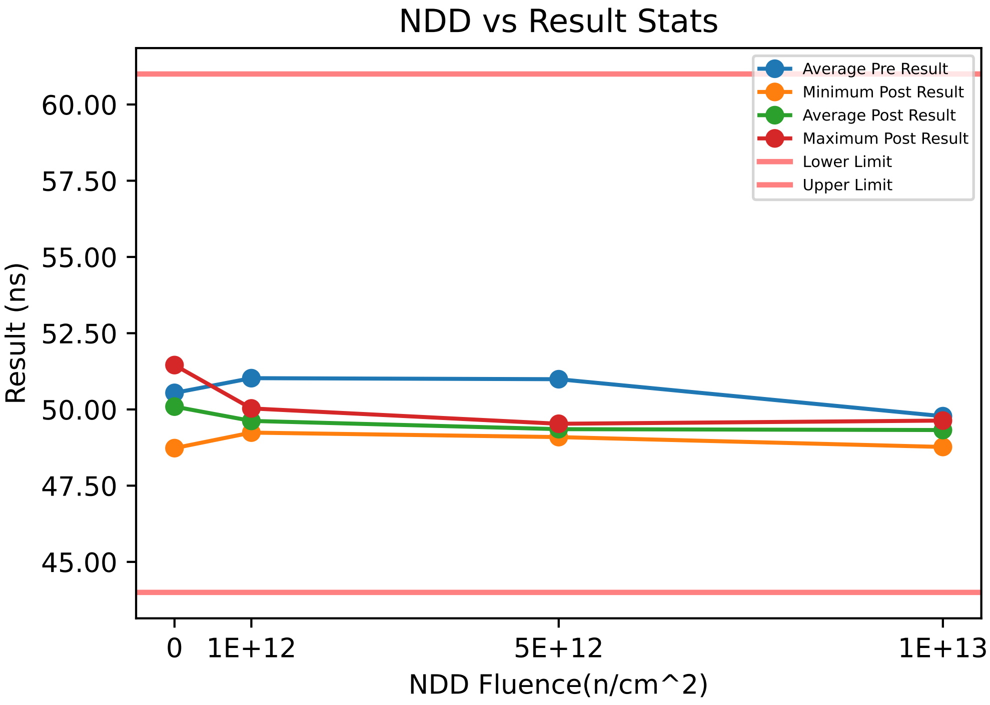
Test Results (Lower Limit = 16.0, Upper Limit = 24.5 (ns))

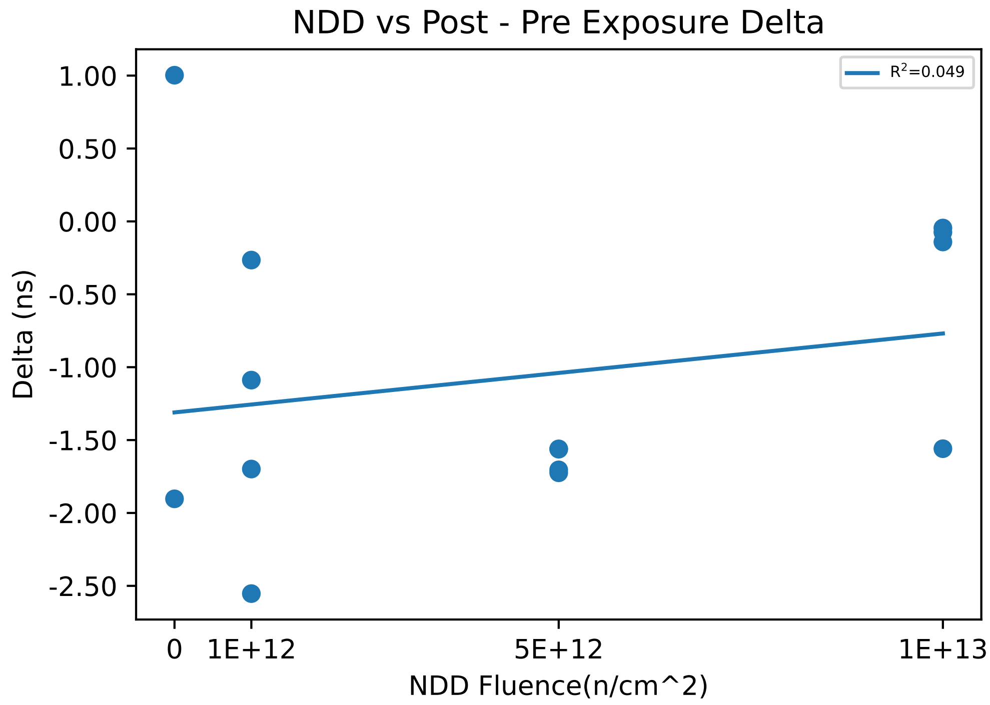
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	20.476	18.93	-1.5451
2	0	Correlation	20.475	19.641	-0.8343
30	1e+12	NDD unbiased	20.547	19.127	-1.4195
31	1e+12	NDD unbiased	20.943	19.018	-1.9251
32	1e+12	NDD unbiased	20.543	18.888	-1.6548
33	1e+12	NDD unbiased	19.39	19.178	-0.2116
44	5e+12	NDD unbiased	20.942	19.476	-1.4659
45	5e+12	NDD unbiased	20.506	19.189	-1.3163
46	5e+12	NDD unbiased	20.491	18.737	-1.7534
47	5e+12	NDD unbiased	20.778	19.154	-1.6244
50	1e+13	NDD unbiased	18.794	18.727	-0.0667
51	1e+13	NDD unbiased	21.006	19.372	-1.6342
52	1e+13	NDD unbiased	19.514	19.387	-0.1267
53	1e+13	NDD unbiased	19.176	19.107	-0.0691

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	20.475	20.475	20.476	0.00042426	18.93	19.286	19.641	0.50219	-1.5451	-1.1897	-0.8343	0.50261
1e+12	19.39	20.356	20.943	0.67087	18.888	19.053	19.178	0.1287	-1.9251	-1.3028	-0.2116	0.7562
5e+12	20.491	20.679	20.942	0.21935	18.737	19.139	19.476	0.30417	-1.7534	-1.54	-1.3163	0.18991
1e+13	18.794	19.623	21.006	0.96833	18.727	19.148	19.387	0.3088	-1.6342	-0.47418	-0.0667	0.77385

Device Test: 95.32 T_RHL_LARGE(_DHL Dead Time Large 2MHz VIN_10V)


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

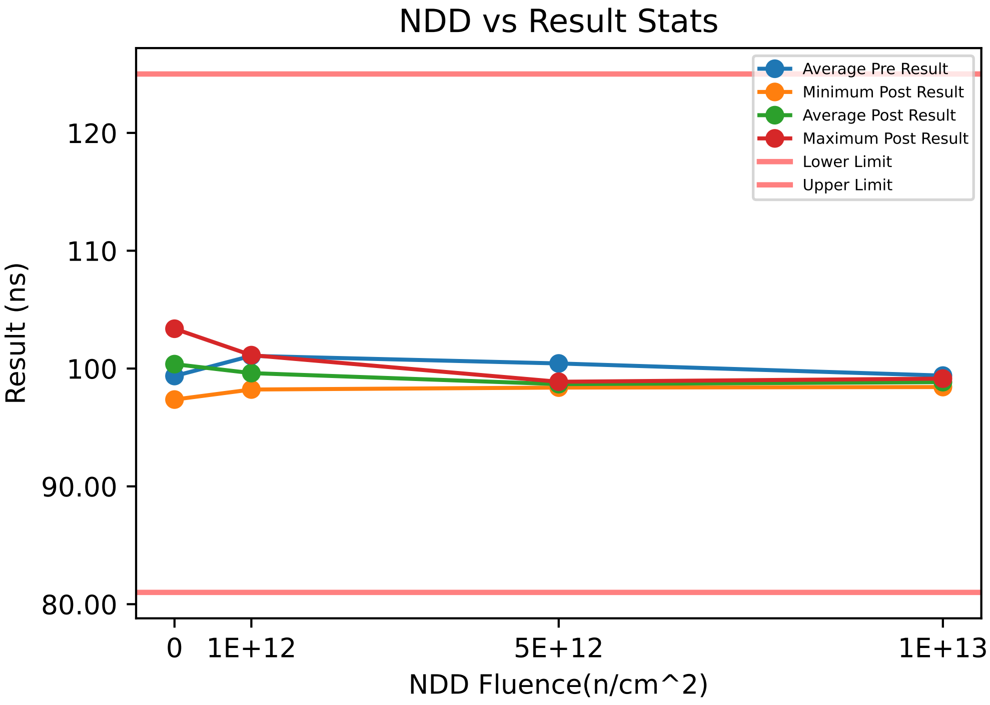
Test Results (Lower Limit = 44.0, Upper Limit = 61.0 (ns))

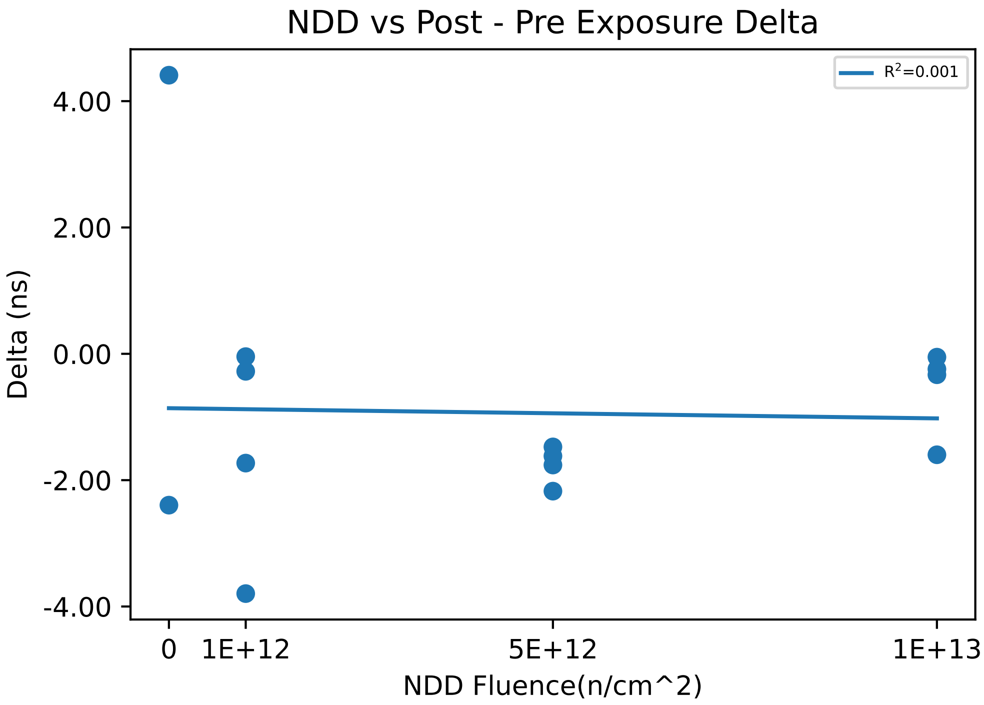
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	50.634	48.731	-1.9031
2	0	Correlation	50.452	51.455	1.0028
30	1e+12	NDD unbiased	51.122	50.033	-1.0887
31	1e+12	NDD unbiased	51.849	49.295	-2.5531
32	1e+12	NDD unbiased	51.625	49.926	-1.6987
33	1e+12	NDD unbiased	49.506	49.24	-0.2653
44	5e+12	NDD unbiased	51.092	49.53	-1.5623
45	5e+12	NDD unbiased	51.149	49.444	-1.7043
46	5e+12	NDD unbiased	50.817	49.093	-1.7245
47	5e+12	NDD unbiased	50.907	49.346	-1.5604
50	1e+13	NDD unbiased	48.844	48.769	-0.0743
51	1e+13	NDD unbiased	51.194	49.635	-1.5592
52	1e+13	NDD unbiased	49.637	49.592	-0.0454
53	1e+13	NDD unbiased	49.442	49.3	-0.1411

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	50.452	50.543	50.634	0.12862	48.731	50.093	51.455	1.9262	-1.9031	-0.45015	1.0028	2.0548
1e+12	49.506	51.025	51.849	1.0577	49.24	49.624	50.033	0.41397	-2.5531	-1.4015	-0.2653	0.96666
5e+12	50.817	50.991	51.149	0.15534	49.093	49.353	49.53	0.18921	-1.7245	-1.6379	-1.5604	0.088751
1e+13	48.844	49.779	51.194	1.0018	48.769	49.324	49.635	0.39853	-1.5592	-0.455	-0.0454	0.73722

Device Test: 95.33 T_RHL_MAX(_DHL Dead Time Max 2MHz VIN_10V)


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

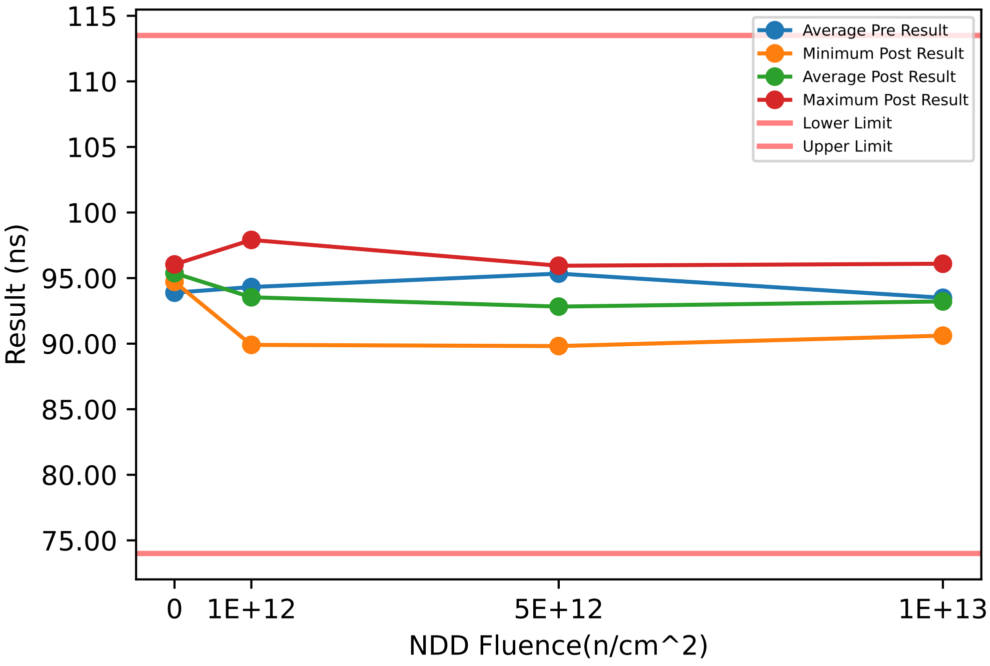
Test Results (Lower Limit = 81.0, Upper Limit = 125.0 (ns))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	99.763	97.368	-2.3957
2	0	Correlation	98.969	103.38	4.4106
30	1e+12	NDD unbiased	100.49	100.44	-0.0444
31	1e+12	NDD unbiased	102.45	98.652	-3.7959
32	1e+12	NDD unbiased	102.87	101.14	-1.73
33	1e+12	NDD unbiased	98.497	98.22	-0.2773
44	5e+12	NDD unbiased	99.858	98.384	-1.4737
45	5e+12	NDD unbiased	101.05	98.879	-2.1741
46	5e+12	NDD unbiased	100.32	98.699	-1.6183
47	5e+12	NDD unbiased	100.5	98.741	-1.7604
50	1e+13	NDD unbiased	98.672	98.43	-0.2425
51	1e+13	NDD unbiased	100.64	99.039	-1.598
52	1e+13	NDD unbiased	99.098	98.767	-0.3312
53	1e+13	NDD unbiased	99.198	99.145	-0.053

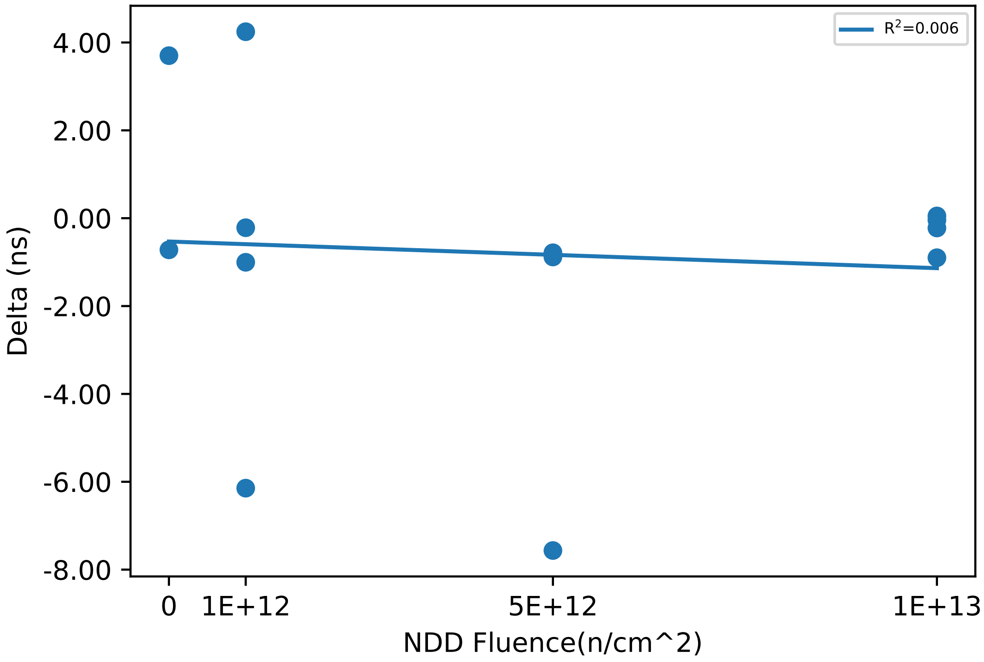
Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	98.969	99.366	99.763	0.56201	97.368	100.37	103.38	4.2508	-2.3957	1.0075	4.4106	4.8128
1e+12	98.497	101.08	102.87	2.0071	98.22	99.613	101.14	1.3999	-3.7959	-1.4619	-0.0444	1.7255
5e+12	99.858	100.43	101.05	0.49466	98.384	98.676	98.879	0.20934	-2.1741	-1.7566	-1.4737	0.30193
1e+13	98.672	99.401	100.64	0.8548	98.43	98.845	99.145	0.3195	-1.598	-0.55617	-0.053	0.70418

Device Test: 95.4 T_RLH_MAX(_DLH Dead Time Max 500kMHz VIN_10V)



NDD vs Result Stats



NDD vs Post - Pre Exposure Delta

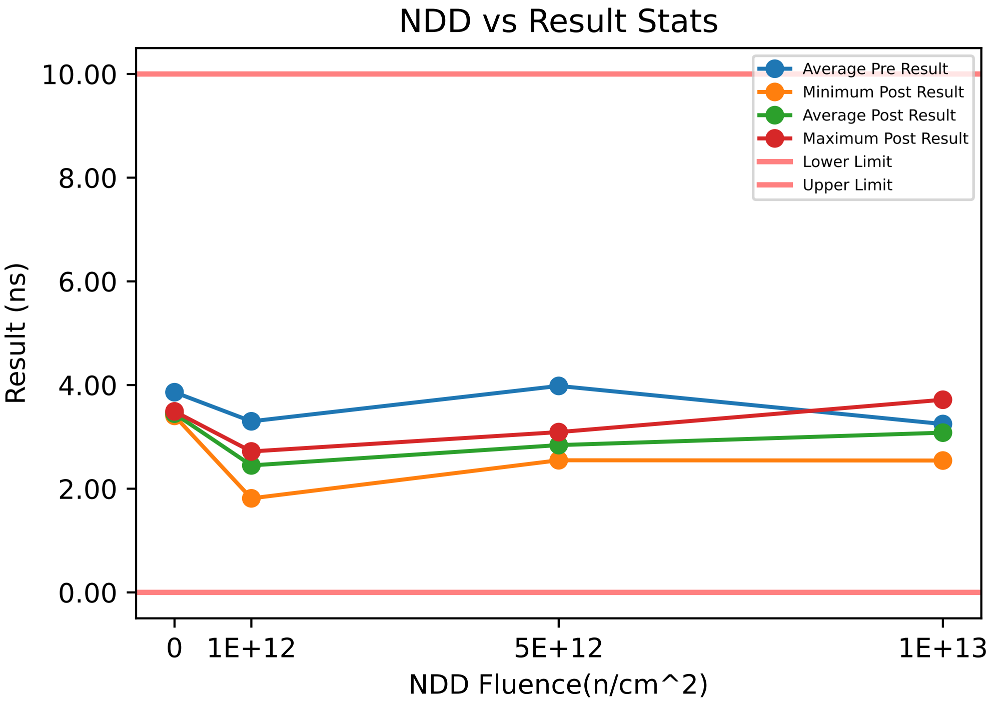
Test Results (Lower Limit = 74.0, Upper Limit = 113.5 (ns))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	91.013	94.713	3.7001
2	0	Correlation	96.761	96.041	-0.72
30	1e+12	NDD unbiased	91.609	95.854	4.245
31	1e+12	NDD unbiased	96.622	90.477	-6.1454
32	1e+12	NDD unbiased	90.911	89.907	-1.0036
33	1e+12	NDD unbiased	98.128	97.911	-0.2167
44	5e+12	NDD unbiased	96.597	95.715	-0.8823
45	5e+12	NDD unbiased	97.381	89.816	-7.5648
46	5e+12	NDD unbiased	96.73	95.942	-0.7871
47	5e+12	NDD unbiased	90.657	89.832	-0.8247
50	1e+13	NDD unbiased	95.075	94.853	-0.2225
51	1e+13	NDD unbiased	91.51	90.61	-0.8999
52	1e+13	NDD unbiased	91.364	91.323	-0.0409
53	1e+13	NDD unbiased	96.043	96.094	0.0507

Test Statistics (ns)

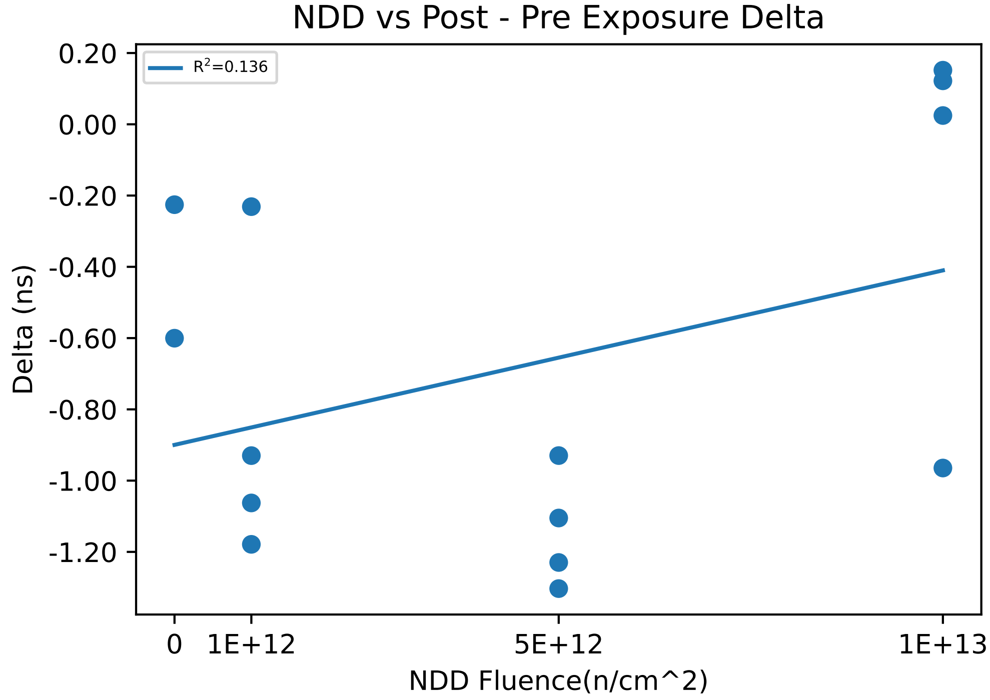
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	91.013	93.887	96.761	4.064	94.713	95.377	96.041	0.93854	-0.72	1.4901	3.7001	3.1255
1e+12	90.911	94.318	98.128	3.5951	89.907	93.537	97.911	3.9598	-6.1454	-0.78018	4.245	4.2585
5e+12	90.657	95.341	97.381	3.1415	89.816	92.827	95.942	3.468	-7.5648	-2.5147	-0.7871	3.3669
1e+13	91.364	93.498	96.043	2.4133	90.61	93.22	96.094	2.6668	-0.8999	-0.27815	0.0507	0.42977

Device Test: 95.5 T_RLH_MIN(_DLH Dead Time Min 1MHz VIN_10V)



Test Results (Lower Limit = 0.0, Upper Limit = 10.0 (ns))

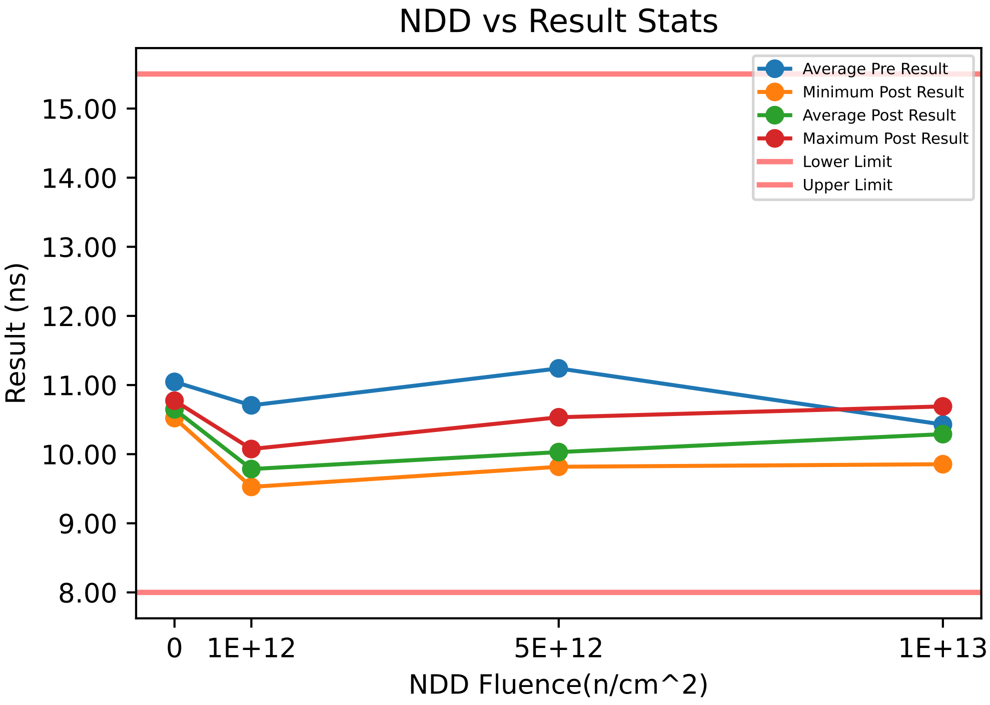
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	4.0056	3.4053	-0.6003
2	0	Correlation	3.7175	3.4919	-0.2256
30	1e+12	NDD unbiased	3.7718	2.593	-1.1788
31	1e+12	NDD unbiased	3.6019	2.6721	-0.9298
32	1e+12	NDD unbiased	3.7814	2.7188	-1.0626
33	1e+12	NDD unbiased	2.0454	1.8143	-0.2311
44	5e+12	NDD unbiased	3.4785	2.5488	-0.9297
45	5e+12	NDD unbiased	4.1664	2.8634	-1.303
46	5e+12	NDD unbiased	4.1969	3.092	-1.1049
47	5e+12	NDD unbiased	4.09	2.8603	-1.2297
50	1e+13	NDD unbiased	2.3919	2.5437	0.1518
51	1e+13	NDD unbiased	4.6809	3.7163	-0.9646
52	1e+13	NDD unbiased	2.7988	2.8234	0.0246
53	1e+13	NDD unbiased	3.12	3.242	0.122

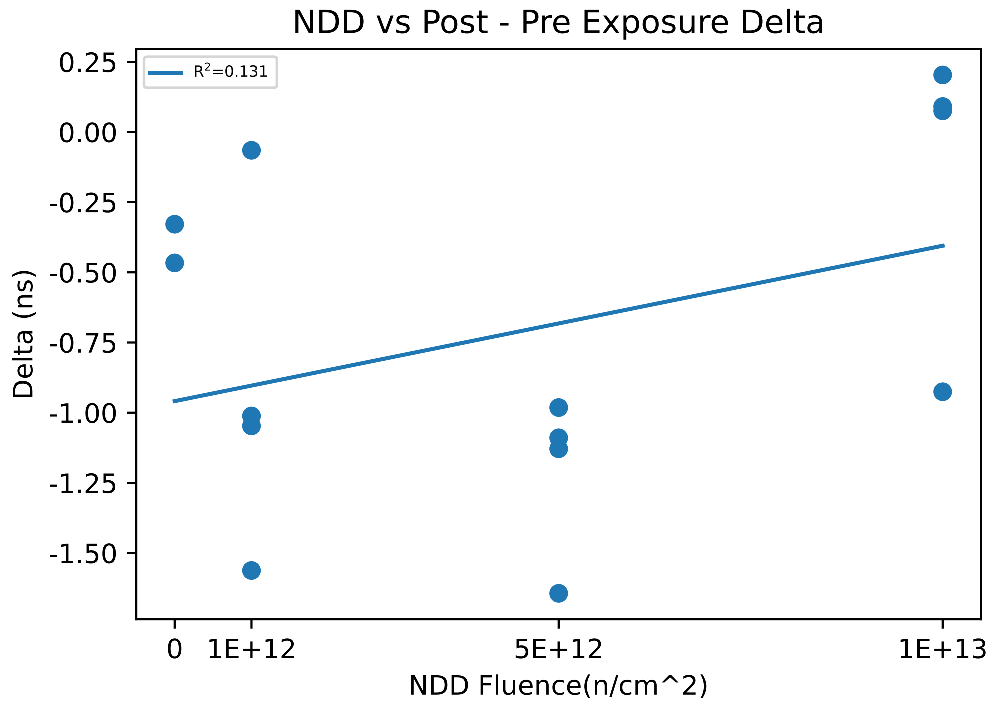


Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.7175	3.8616	4.0056	0.20372	3.4053	3.4486	3.4919	0.061235	-0.6003	-0.41295	-0.2256	0.26495
1e+12	2.0454	3.3001	3.7814	0.84054	1.8143	2.4495	2.7188	0.42667	-1.1788	-0.85058	-0.2311	0.42533
5e+12	3.4785	3.983	4.1969	0.33929	2.5488	2.8411	3.092	0.22305	-1.303	-1.1418	-0.9297	0.16336
1e+13	2.3919	3.2479	4.6809	1.0007	2.5437	3.0814	3.7163	0.5114	-0.9646	-0.16655	0.1518	0.5348

Device Test: 95.6 T_RLH_SMALL(_DLH Dead Time Small 1MHz VIN_10V)


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

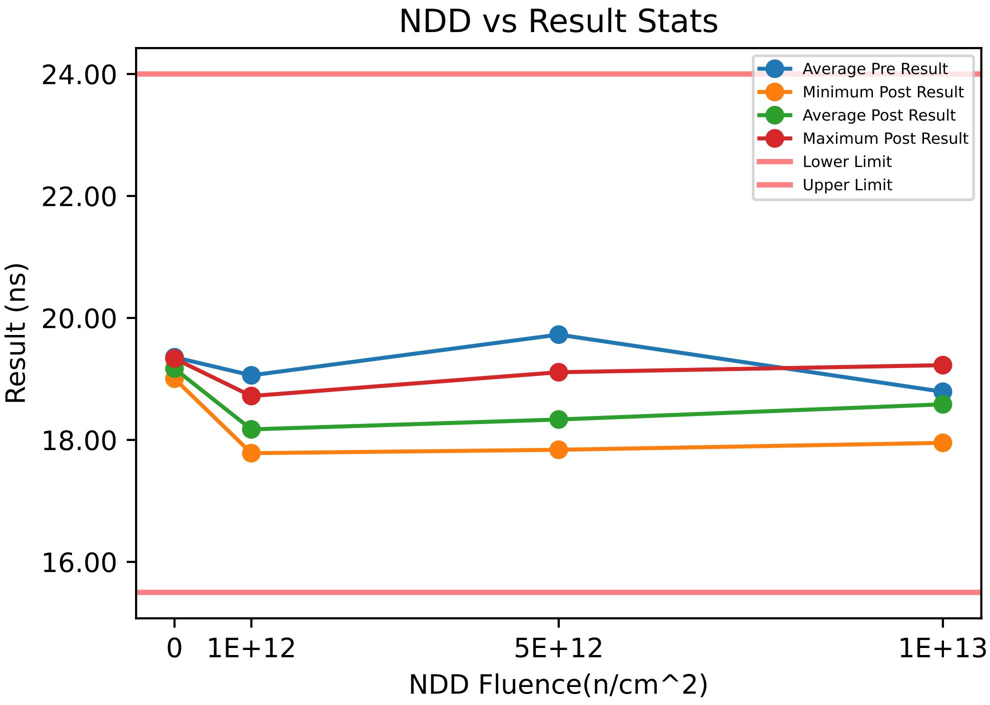
Test Results (Lower Limit = 8.0, Upper Limit = 15.5 (ns))

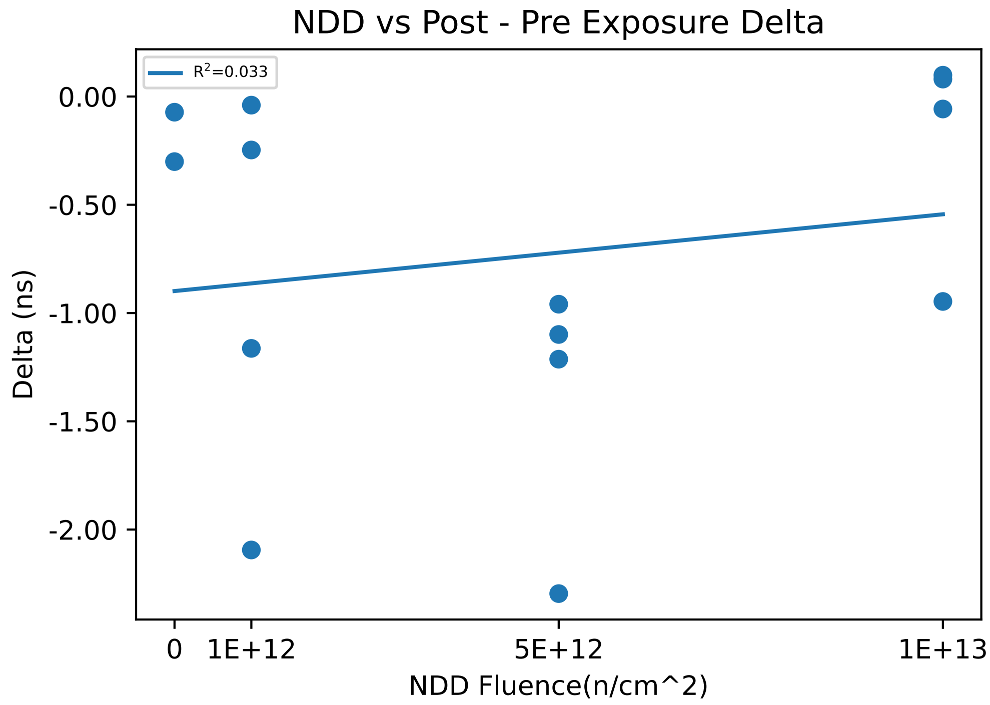
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	10.989	10.523	-0.4664
2	0	Correlation	11.102	10.774	-0.3286
30	1e+12	NDD unbiased	11.086	10.075	-1.0117
31	1e+12	NDD unbiased	11.344	9.7817	-1.5624
32	1e+12	NDD unbiased	10.803	9.7562	-1.0472
33	1e+12	NDD unbiased	9.5915	9.5263	-0.0652
44	5e+12	NDD unbiased	11.001	9.9112	-1.0896
45	5e+12	NDD unbiased	11.501	9.8572	-1.6438
46	5e+12	NDD unbiased	11.515	10.534	-0.9818
47	5e+12	NDD unbiased	10.946	9.8176	-1.1287
50	1e+13	NDD unbiased	9.7914	9.9947	0.2033
51	1e+13	NDD unbiased	11.544	10.619	-0.9255
52	1e+13	NDD unbiased	9.779	9.8544	0.0754
53	1e+13	NDD unbiased	10.6	10.691	0.0908

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	10.989	11.046	11.102	0.080186	10.523	10.648	10.774	0.17763	-0.4664	-0.3975	-0.3286	0.097439
1e+12	9.5915	10.706	11.344	0.77531	9.5263	9.7847	10.075	0.22478	-1.5624	-0.92162	-0.0652	0.62395
5e+12	10.946	11.241	11.515	0.30957	9.8176	10.03	10.534	0.33803	-1.6438	-1.211	-0.9818	0.29516
1e+13	9.779	10.429	11.544	0.83705	9.8544	10.29	10.691	0.42647	-0.9255	-0.139	0.2033	0.52742

Device Test: 95.7 T_RLH_MID(_DLH Dead Time Mid 1MHz VIN_10V)


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

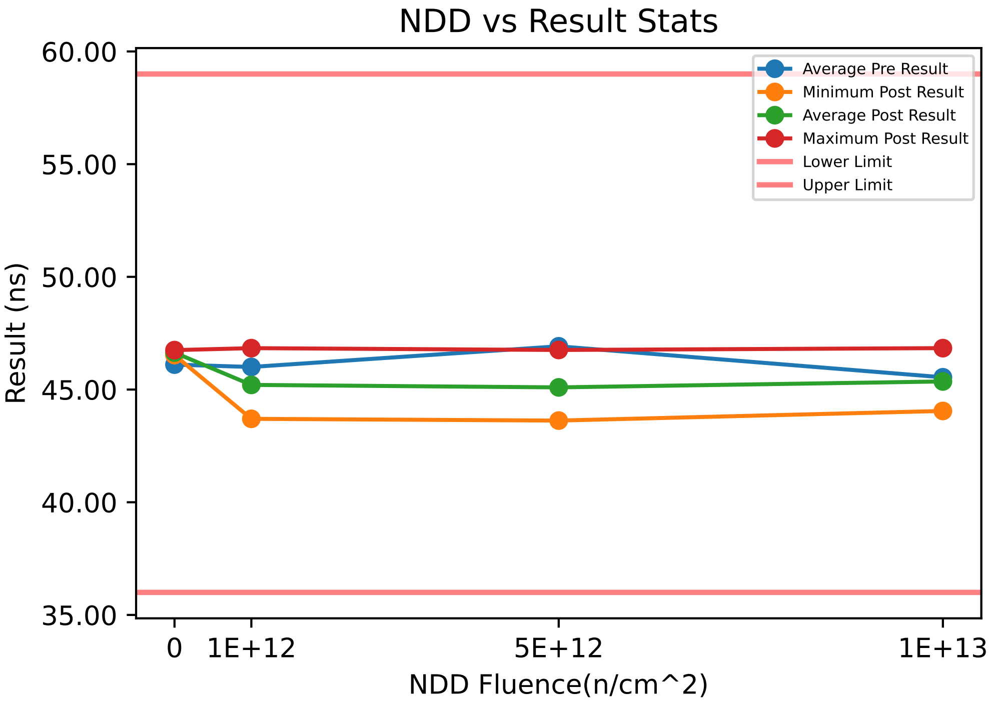
Test Results (Lower Limit = 15.5, Upper Limit = 24.0 (ns))

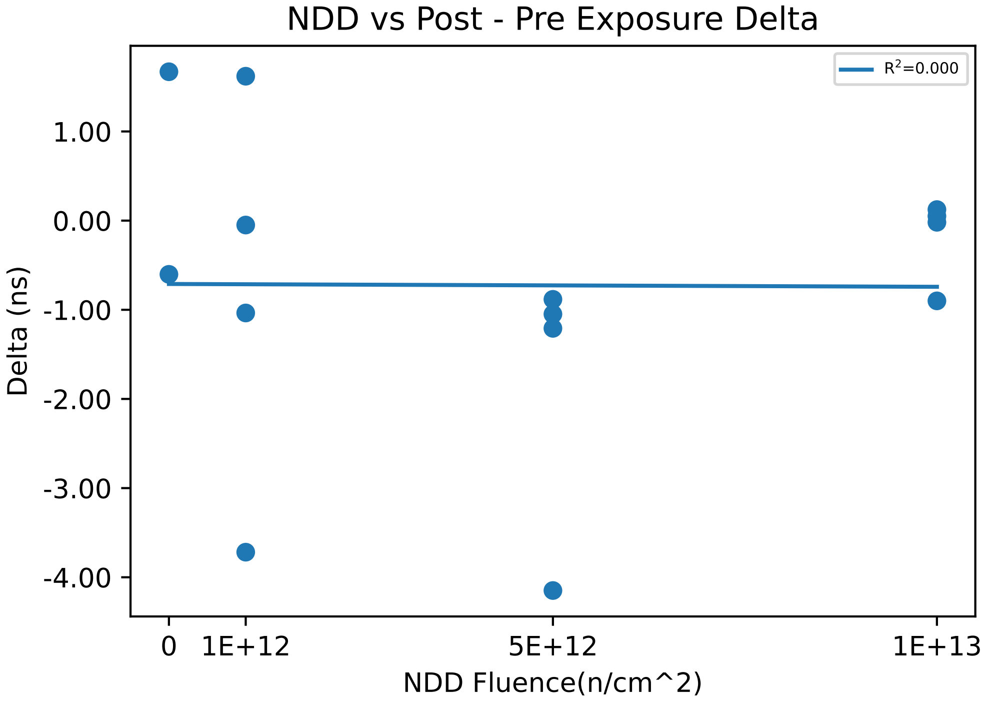
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	19.077	19.005	-0.0724
2	0	Correlation	19.635	19.335	-0.3006
30	1e+12	NDD unbiased	18.967	18.72	-0.2469
31	1e+12	NDD unbiased	19.877	17.783	-2.0943
32	1e+12	NDD unbiased	19.012	17.849	-1.1632
33	1e+12	NDD unbiased	18.381	18.341	-0.0398
44	5e+12	NDD unbiased	19.646	18.547	-1.099
45	5e+12	NDD unbiased	20.14	17.844	-2.2958
46	5e+12	NDD unbiased	20.069	19.11	-0.9592
47	5e+12	NDD unbiased	19.052	17.838	-1.2131
50	1e+13	NDD unbiased	18.375	18.474	0.0985
51	1e+13	NDD unbiased	19.63	18.683	-0.9465
52	1e+13	NDD unbiased	18.009	17.952	-0.0576
53	1e+13	NDD unbiased	19.145	19.226	0.0805

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	19.077	19.356	19.635	0.39478	19.005	19.17	19.335	0.23342	-0.3006	-0.1865	-0.0724	0.16136
1e+12	18.381	19.059	19.877	0.61637	17.783	18.173	18.72	0.44153	-2.0943	-0.88605	-0.0398	0.94187
5e+12	19.052	19.727	20.14	0.50004	17.838	18.335	19.11	0.61457	-2.2958	-1.3918	-0.9592	0.61156
1e+13	18.009	18.79	19.63	0.73324	17.952	18.584	19.226	0.52709	-0.9465	-0.20627	0.0985	0.49839

Device Test: 95.8 T_RLH_LARGE(_DLH Dead Time Large 1MHz VIN_10V)


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

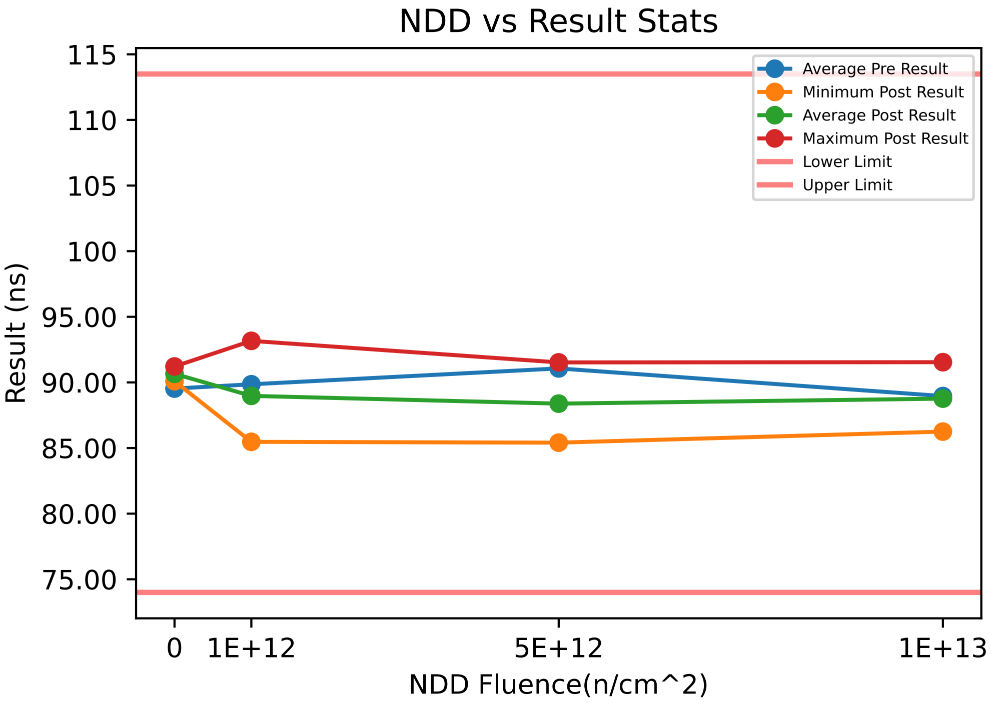
Test Results (Lower Limit = 36.0, Upper Limit = 59.0 (ns))

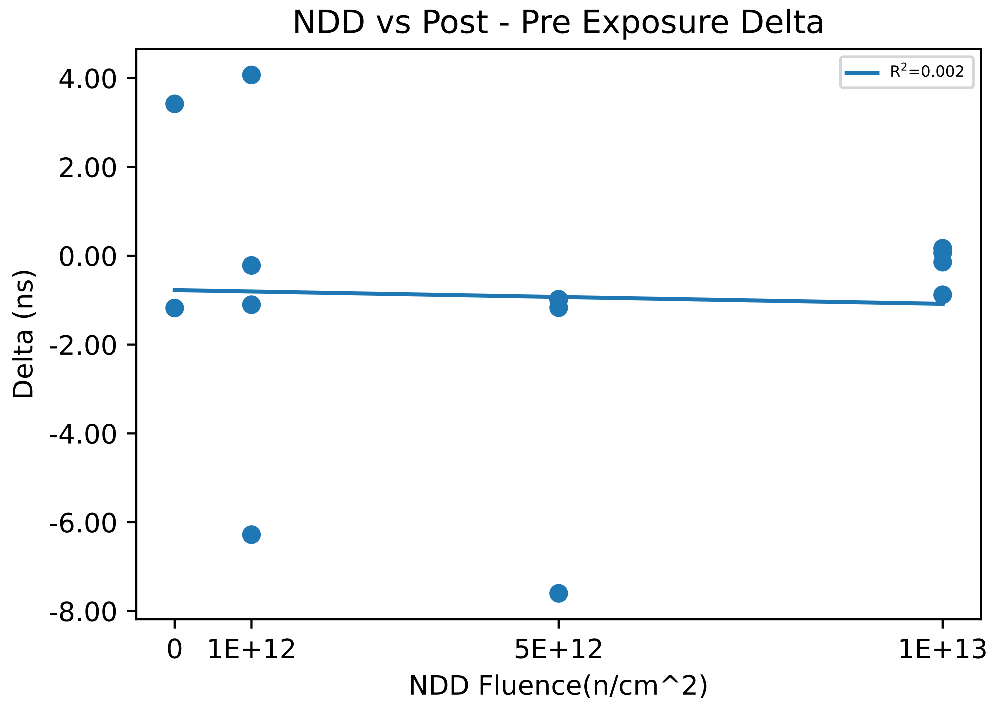
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	44.86	46.529	1.6696
2	0	Correlation	47.352	46.75	-0.6026
30	1e+12	NDD unbiased	44.876	46.495	1.6194
31	1e+12	NDD unbiased	47.51	43.791	-3.7185
32	1e+12	NDD unbiased	44.737	43.701	-1.0358
33	1e+12	NDD unbiased	46.886	46.837	-0.0494
44	5e+12	NDD unbiased	47.417	46.369	-1.0488
45	5e+12	NDD unbiased	47.785	43.637	-4.1486
46	5e+12	NDD unbiased	47.639	46.756	-0.883
47	5e+12	NDD unbiased	44.831	43.623	-1.2083
50	1e+13	NDD unbiased	46.044	46.095	0.0507
51	1e+13	NDD unbiased	45.352	44.452	-0.9
52	1e+13	NDD unbiased	44.069	44.05	-0.0187
53	1e+13	NDD unbiased	46.714	46.837	0.1238

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	44.86	46.106	47.352	1.7624	46.529	46.639	46.75	0.1557	-0.6026	0.5335	1.6696	1.6067
1e+12	44.737	46.002	47.51	1.4052	43.701	45.206	46.837	1.6919	-3.7185	-0.79608	1.6194	2.2353
5e+12	44.831	46.918	47.785	1.3995	43.623	45.096	46.756	1.7004	-4.1486	-1.8222	-0.883	1.5566
1e+13	44.069	45.545	46.714	1.13	44.05	45.359	46.837	1.3244	-0.9	-0.18605	0.1238	0.47951

Device Test: 95.9 T_RLH_MAX(_DLH Dead Time Max 1MHz VIN_10V)


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

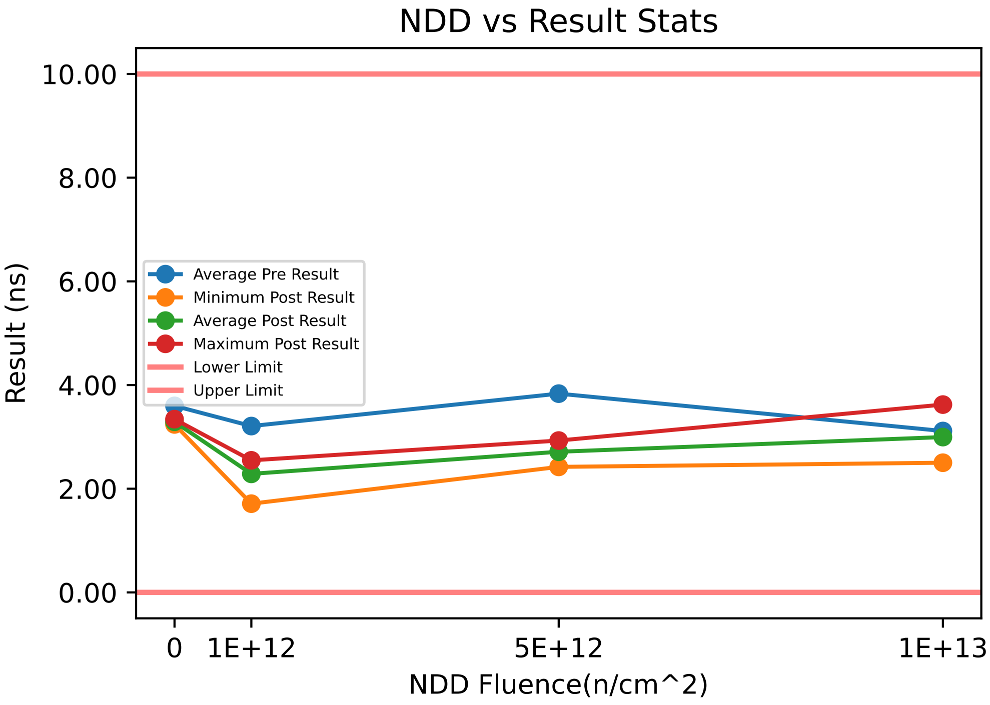
Test Results (Lower Limit = 74.0, Upper Limit = 113.5 (ns))

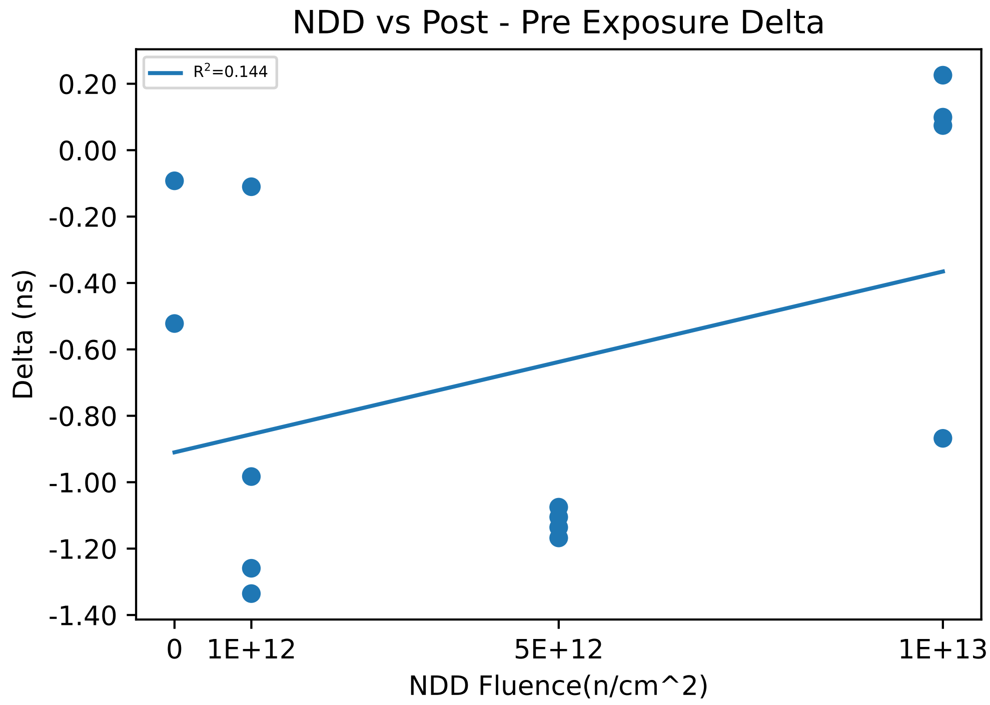
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	86.673	90.093	3.42
2	0	Correlation	92.39	91.214	-1.1766
30	1e+12	NDD unbiased	87.196	91.267	4.071
31	1e+12	NDD unbiased	92.275	85.995	-6.2797
32	1e+12	NDD unbiased	86.574	85.472	-1.1022
33	1e+12	NDD unbiased	93.384	93.166	-0.218
44	5e+12	NDD unbiased	92.14	91.158	-0.9818
45	5e+12	NDD unbiased	93.011	85.41	-7.6012
46	5e+12	NDD unbiased	92.505	91.525	-0.9797
47	5e+12	NDD unbiased	86.609	85.44	-1.1691
50	1e+13	NDD unbiased	90.558	90.414	-0.1439
51	1e+13	NDD unbiased	87.131	86.252	-0.8785
52	1e+13	NDD unbiased	86.779	86.845	0.0661
53	1e+13	NDD unbiased	91.372	91.541	0.169

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	86.673	89.532	92.39	4.0425	90.093	90.654	91.214	0.79224	-1.1766	1.1217	3.42	3.2503
1e+12	86.574	89.857	93.384	3.4711	85.472	88.975	93.166	3.8284	-6.2797	-0.88223	4.071	4.2488
5e+12	86.609	91.066	93.011	2.9927	85.41	88.383	91.525	3.4193	-7.6012	-2.683	-0.9797	3.28
1e+13	86.779	88.96	91.372	2.3434	86.252	88.763	91.541	2.6093	-0.8785	-0.19682	0.169	0.47274

Device Test: 96.0 T_RLH_MIN(_DLH Dead Time Min 500kHz VIN_12V)





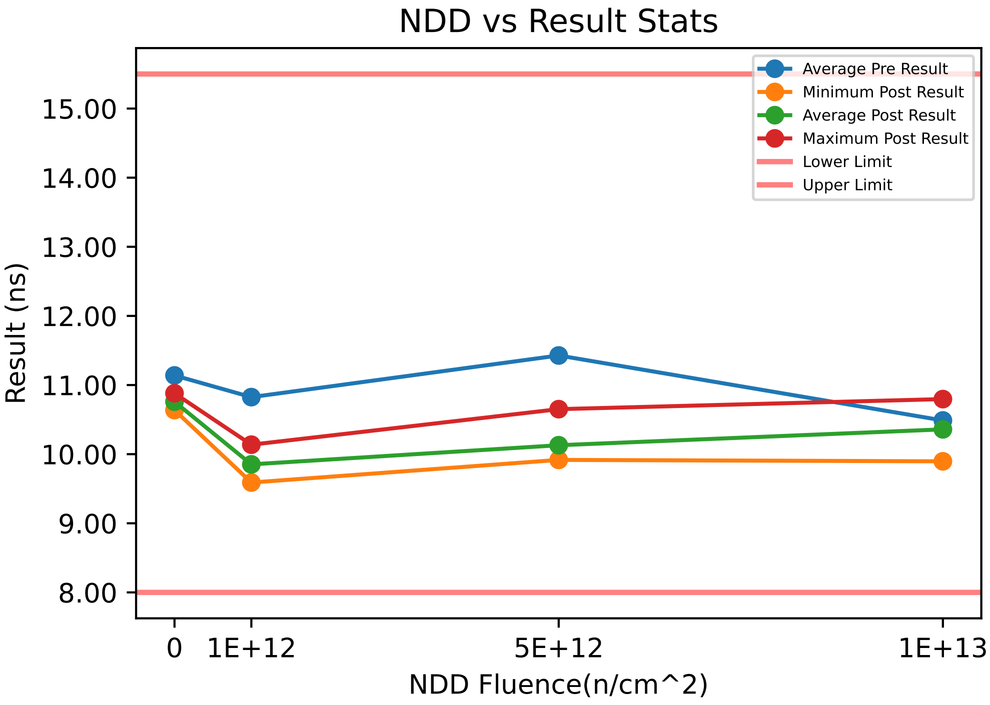
Test Results (Lower Limit = 0.0, Upper Limit = 10.0 (ns))

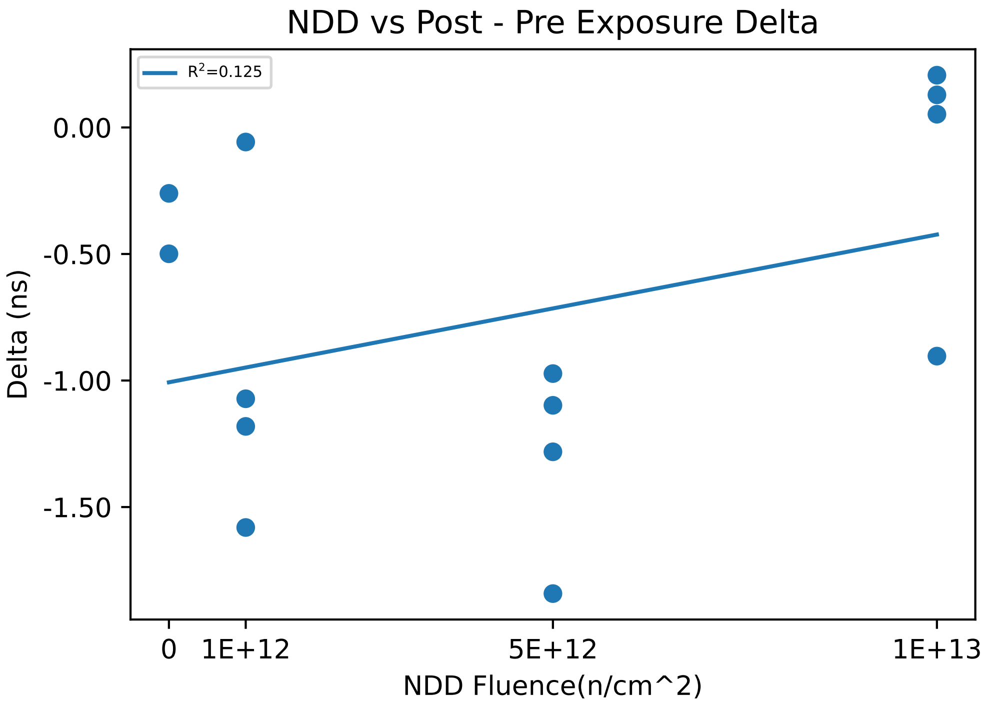
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	3.7625	3.2404	-0.5221
2	0	Correlation	3.4342	3.3419	-0.0923
30	1e+12	NDD unbiased	3.7672	2.4317	-1.3355
31	1e+12	NDD unbiased	3.5305	2.5475	-0.983
32	1e+12	NDD unbiased	3.7153	2.4561	-1.2592
33	1e+12	NDD unbiased	1.8215	1.7114	-0.1101
44	5e+12	NDD unbiased	3.4965	2.4213	-1.0752
45	5e+12	NDD unbiased	3.9066	2.7388	-1.1678
46	5e+12	NDD unbiased	4.0342	2.9291	-1.1051
47	5e+12	NDD unbiased	3.8989	2.7629	-1.136
50	1e+13	NDD unbiased	2.4271	2.5013	0.0742
51	1e+13	NDD unbiased	4.4907	3.6228	-0.8679
52	1e+13	NDD unbiased	2.5244	2.7502	0.2258
53	1e+13	NDD unbiased	3.0104	3.1098	0.0994

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.4342	3.5983	3.7625	0.23214	3.2404	3.2912	3.3419	0.071771	-0.5221	-0.3072	-0.0923	0.30391
1e+12	1.8215	3.2086	3.7672	0.93031	1.7114	2.2867	2.5475	0.38674	-1.3355	-0.92195	-0.1101	0.56202
5e+12	3.4965	3.834	4.0342	0.23343	2.4213	2.713	2.9291	0.21209	-1.1678	-1.121	-1.0752	0.039857
1e+13	2.4271	3.1132	4.4907	0.95315	2.5013	2.996	3.6228	0.48682	-0.8679	-0.11713	0.2258	0.50489

Device Test: 96.1 T_RLH_SMALL(_DLH Dead Time Small 500kHz VIN_12V)





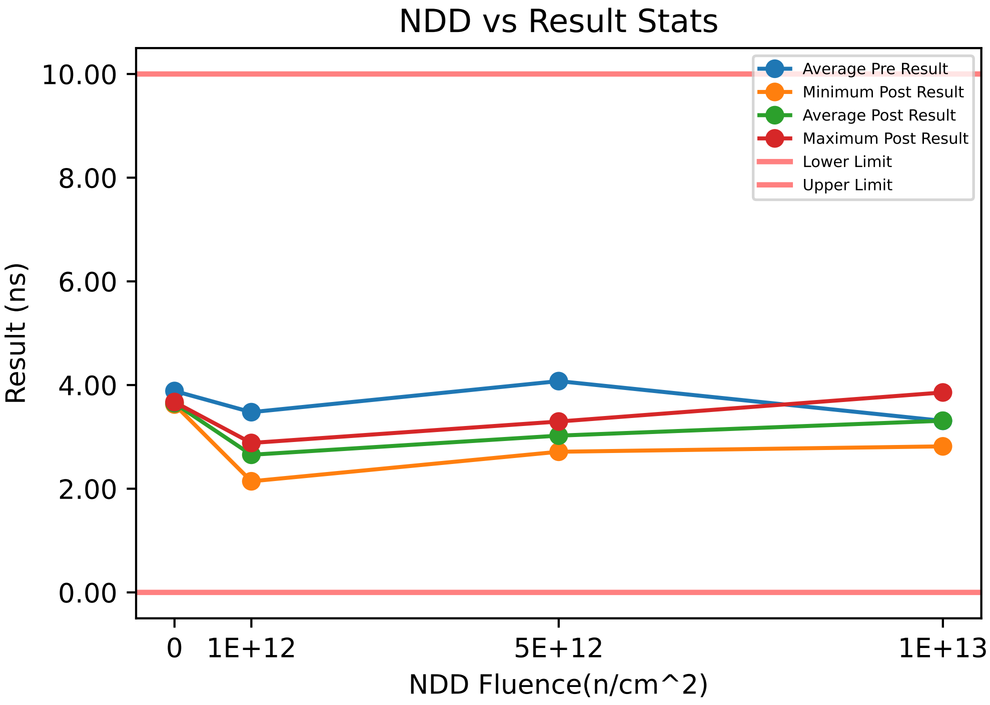
Test Results (Lower Limit = 8.0, Upper Limit = 15.5 (ns))

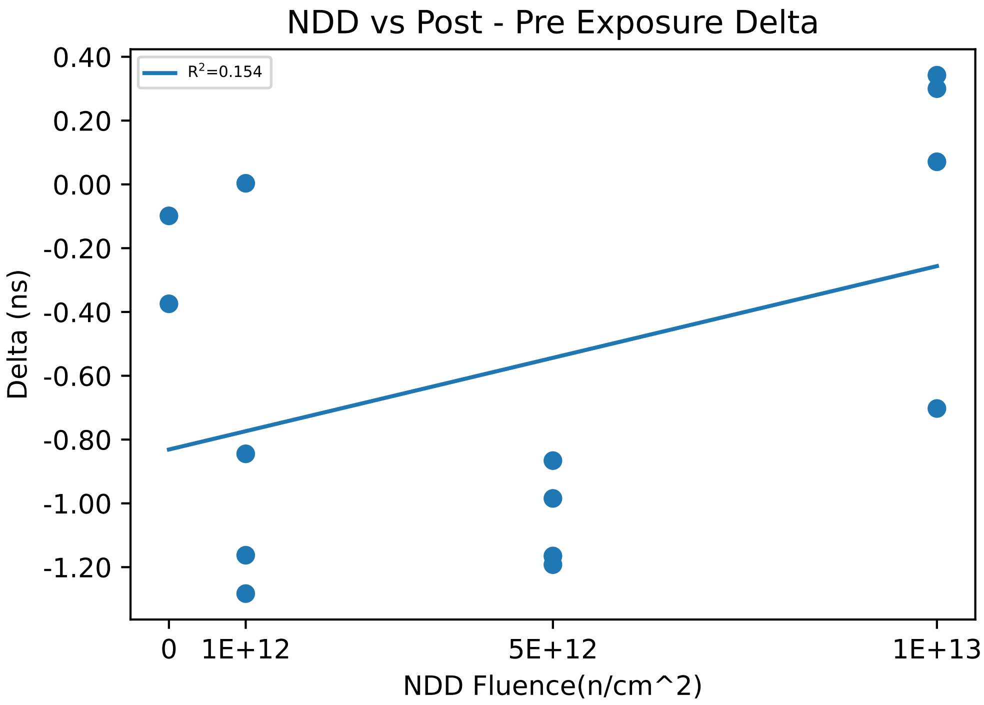
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	11.137	10.638	-0.4992
2	0	Correlation	11.141	10.881	-0.2605
30	1e+12	NDD unbiased	11.209	10.137	-1.0721
31	1e+12	NDD unbiased	11.47	9.8894	-1.5808
32	1e+12	NDD unbiased	10.975	9.7935	-1.1813
33	1e+12	NDD unbiased	9.6471	9.5896	-0.0575
44	5e+12	NDD unbiased	11.002	10.029	-0.9726
45	5e+12	NDD unbiased	11.759	9.9169	-1.842
46	5e+12	NDD unbiased	11.749	10.651	-1.098
47	5e+12	NDD unbiased	11.201	9.9192	-1.2817
50	1e+13	NDD unbiased	9.835	10.041	0.2065
51	1e+13	NDD unbiased	11.604	10.701	-0.9036
52	1e+13	NDD unbiased	9.8441	9.8964	0.0523
53	1e+13	NDD unbiased	10.668	10.797	0.1288

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	11.137	11.139	11.141	0.0029698	10.638	10.759	10.881	0.17176	-0.4992	-0.37985	-0.2605	0.16879
1e+12	9.6471	10.825	11.47	0.81113	9.5896	9.8524	10.137	0.22727	-1.5808	-0.97292	-0.0575	0.64827
5e+12	11.002	11.428	11.759	0.38556	9.9169	10.129	10.651	0.35198	-1.842	-1.2986	-0.9726	0.38388
1e+13	9.835	10.488	11.604	0.84053	9.8964	10.359	10.797	0.45573	-0.9036	-0.129	0.2065	0.52022

Device Test: 96.10 T_RLH_MIN(_DLH Dead Time Min 2MHz VIN_12V)





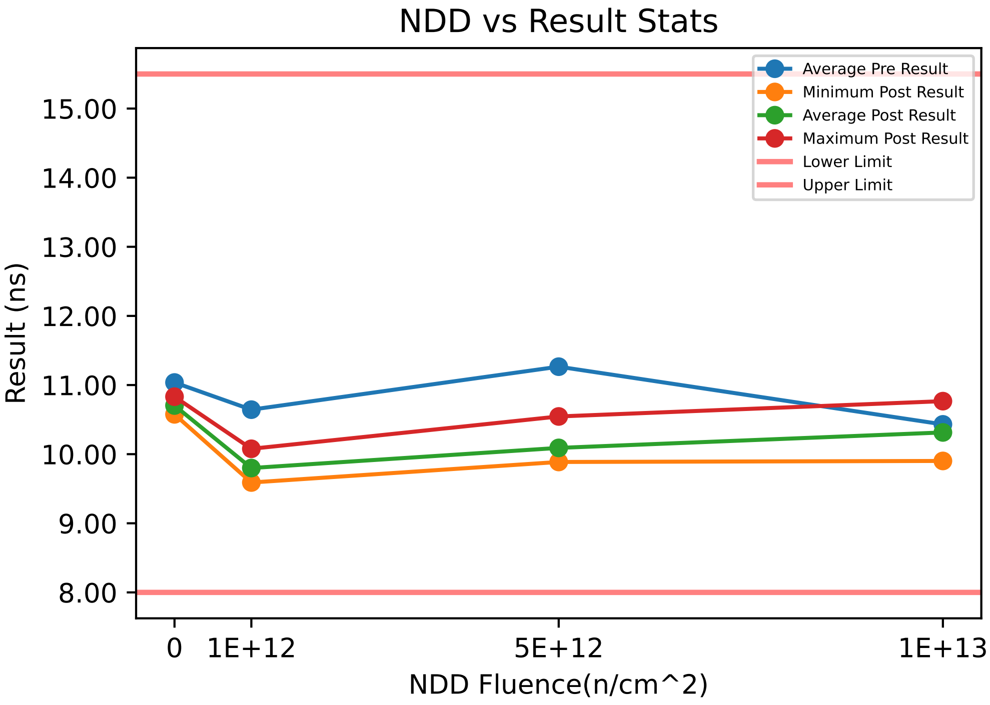
Test Results (Lower Limit = 0.0, Upper Limit = 10.0 (ns))

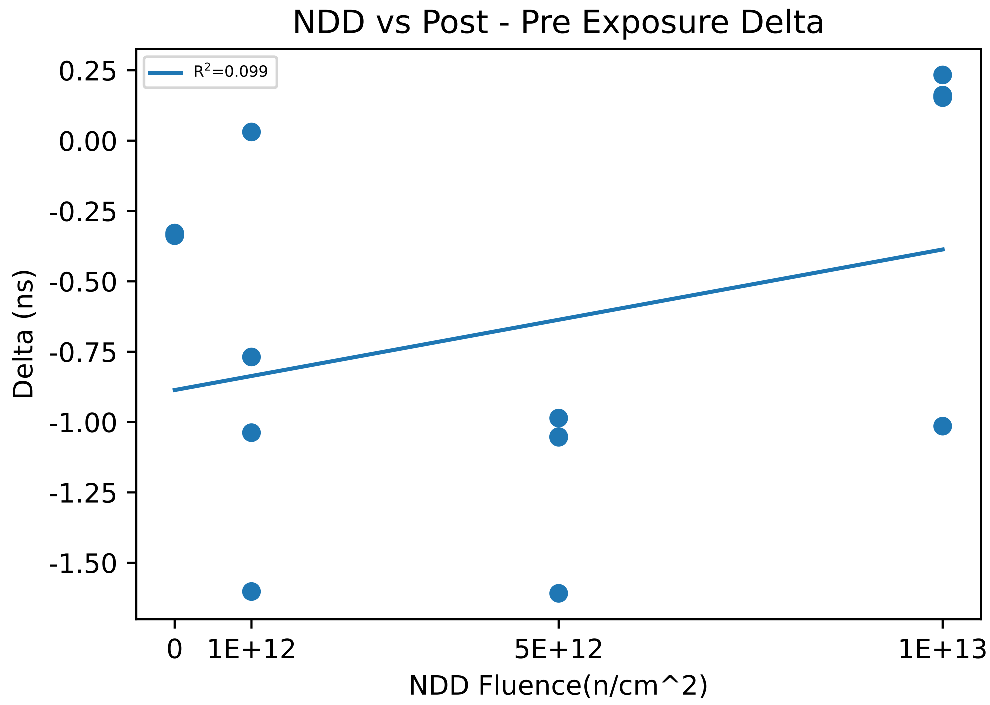
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	3.9988	3.6244	-0.3744
2	0	Correlation	3.7713	3.6726	-0.0987
30	1e+12	NDD unbiased	4.0177	2.7348	-1.2829
31	1e+12	NDD unbiased	3.7274	2.8827	-0.8447
32	1e+12	NDD unbiased	4.0212	2.8586	-1.1626
33	1e+12	NDD unbiased	2.1399	2.1433	0.0034
44	5e+12	NDD unbiased	3.6977	2.7132	-0.9845
45	5e+12	NDD unbiased	4.2369	3.0447	-1.1922
46	5e+12	NDD unbiased	4.1623	3.2963	-0.866
47	5e+12	NDD unbiased	4.2064	3.0414	-1.165
50	1e+13	NDD unbiased	2.4747	2.817	0.3423
51	1e+13	NDD unbiased	4.5594	3.8568	-0.7026
52	1e+13	NDD unbiased	2.8267	3.1268	0.3001
53	1e+13	NDD unbiased	3.3748	3.4457	0.0709

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.7713	3.8851	3.9988	0.16087	3.6244	3.6485	3.6726	0.034083	-0.3744	-0.23655	-0.0987	0.19495
1e+12	2.1399	3.4765	4.0212	0.90167	2.1433	2.6548	2.8827	0.34713	-1.2829	-0.8217	0.0034	0.5803
5e+12	3.6977	4.0758	4.2369	0.25394	2.7132	3.0239	3.2963	0.23908	-1.1922	-1.0519	-0.866	0.15446
1e+13	2.4747	3.3089	4.5594	0.91223	2.817	3.3116	3.8568	0.44497	-0.7026	0.002675	0.3423	0.48507

Device Test: 96.11 T_RLH_SMALL(_DLH Dead Time Small 2MHz VIN_12V)





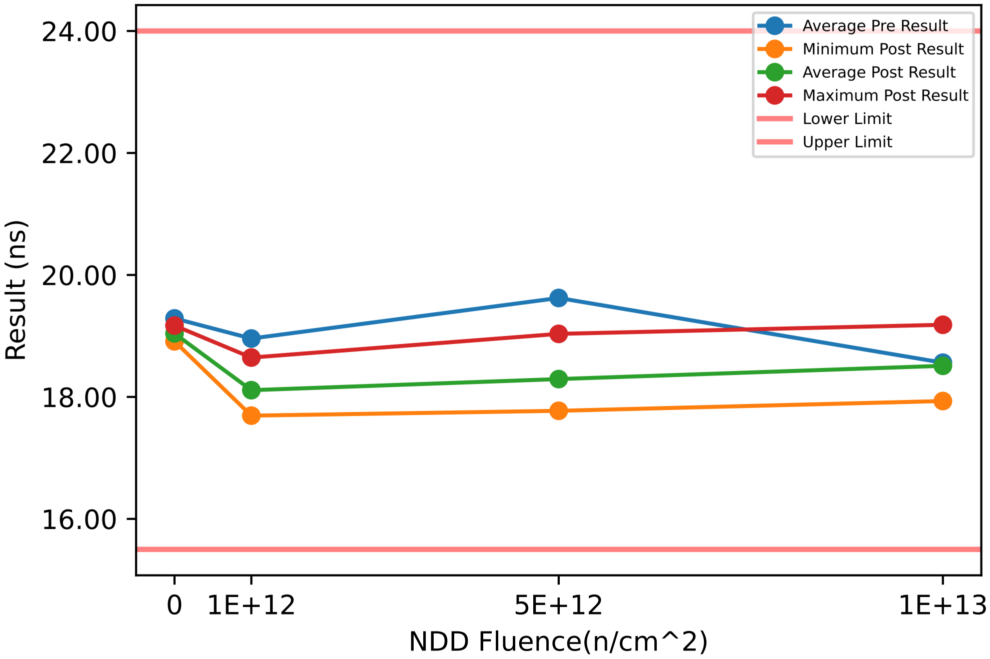
Test Results (Lower Limit = 8.0, Upper Limit = 15.5 (ns))

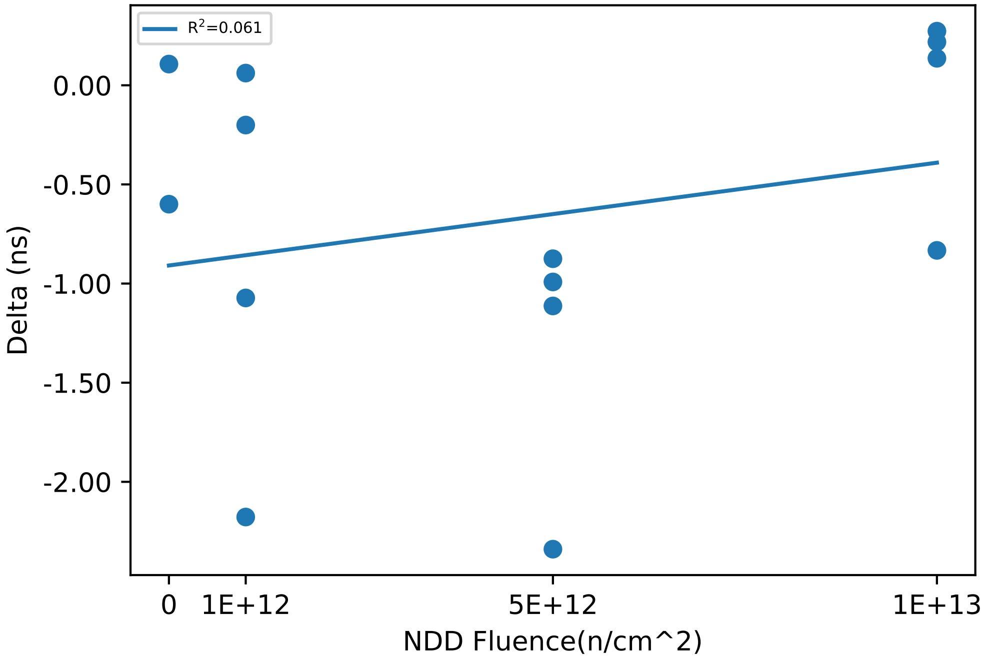
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	10.904	10.576	-0.3282
2	0	Correlation	11.169	10.832	-0.3377
30	1e+12	NDD unbiased	10.846	10.078	-0.7687
31	1e+12	NDD unbiased	11.329	9.7273	-1.6022
32	1e+12	NDD unbiased	10.84	9.8024	-1.0377
33	1e+12	NDD unbiased	9.559	9.5899	0.0309
44	5e+12	NDD unbiased	11.074	10.02	-1.0541
45	5e+12	NDD unbiased	11.496	9.887	-1.6087
46	5e+12	NDD unbiased	11.597	10.545	-1.0517
47	5e+12	NDD unbiased	10.895	9.9096	-0.9858
50	1e+13	NDD unbiased	9.7806	10.014	0.2335
51	1e+13	NDD unbiased	11.589	10.575	-1.0145
52	1e+13	NDD unbiased	9.7489	9.9018	0.1529
53	1e+13	NDD unbiased	10.605	10.767	0.1619

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	10.904	11.037	11.169	0.18738	10.576	10.704	10.832	0.18067	-0.3377	-0.33295	-0.3282	0.0067175
1e+12	9.559	10.644	11.329	0.75863	9.5899	9.7993	10.078	0.20538	-1.6022	-0.84442	0.0309	0.67909
5e+12	10.895	11.266	11.597	0.33488	9.887	10.091	10.545	0.30876	-1.6087	-1.1751	-0.9858	0.29081
1e+13	9.7489	10.431	11.589	0.86785	9.9018	10.314	10.767	0.4214	-1.0145	-0.11655	0.2335	0.59972

Device Test: 96.12 T_RLH_MID(_DLH Dead Time Mid 2MHz VIN_12V)


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

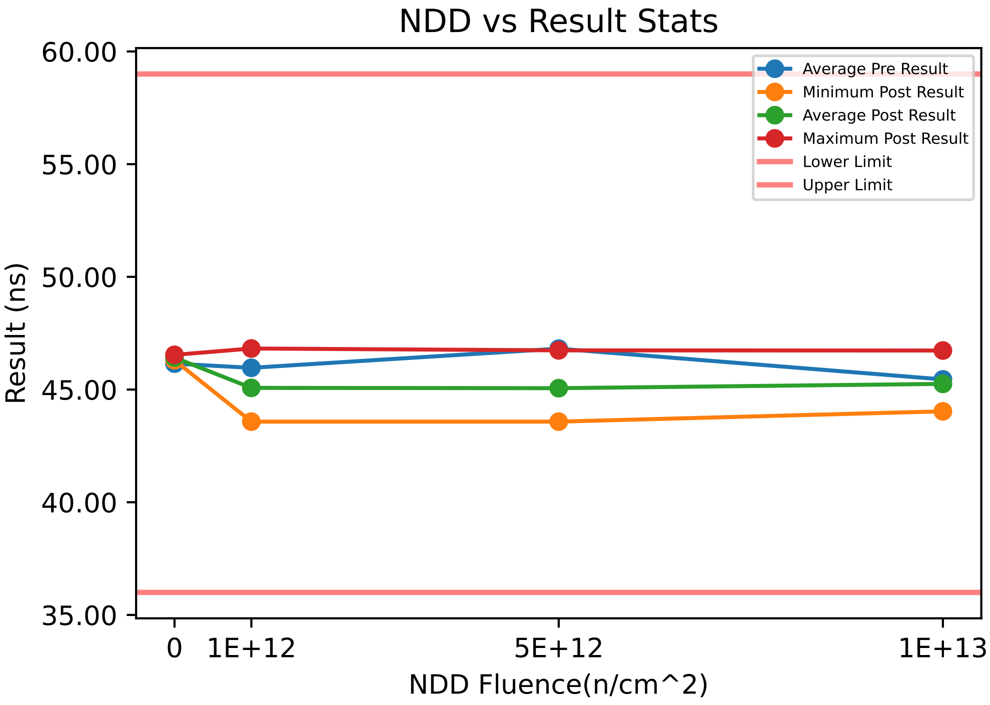
Test Results (Lower Limit = 15.5, Upper Limit = 24.0 (ns))

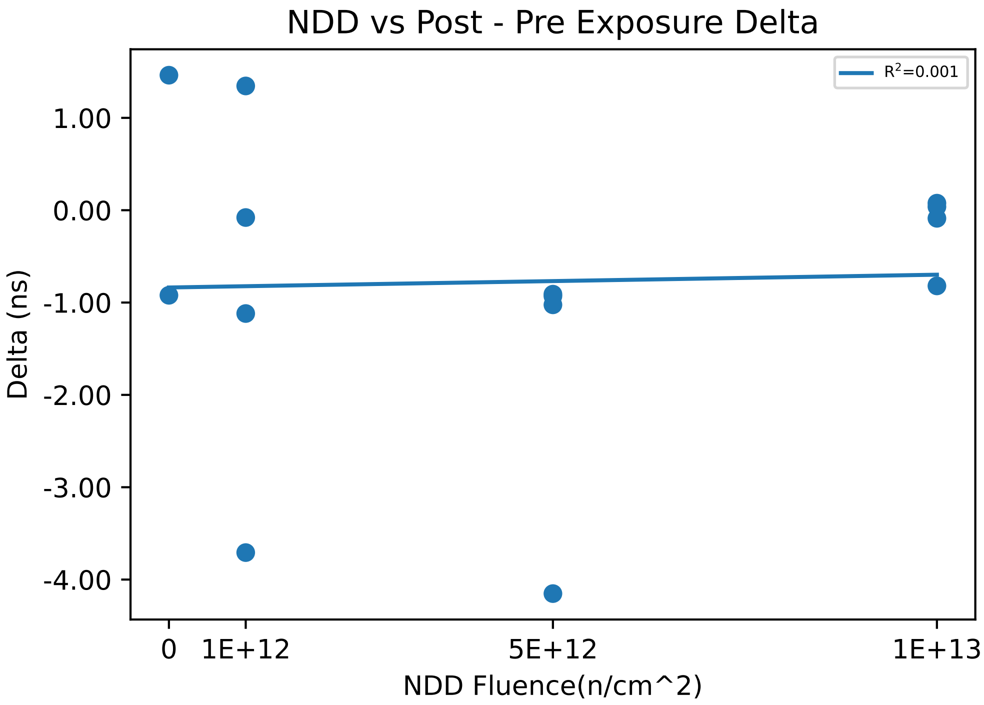
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	18.804	18.911	0.107
2	0	Correlation	19.77	19.171	-0.5996
30	1e+12	NDD unbiased	18.846	18.645	-0.2005
31	1e+12	NDD unbiased	19.871	17.693	-2.1775
32	1e+12	NDD unbiased	18.837	17.765	-1.0725
33	1e+12	NDD unbiased	18.277	18.338	0.0616
44	5e+12	NDD unbiased	19.438	18.564	-0.8748
45	5e+12	NDD unbiased	20.141	17.801	-2.3397
46	5e+12	NDD unbiased	20.026	19.034	-0.9919
47	5e+12	NDD unbiased	18.885	17.772	-1.1129
50	1e+13	NDD unbiased	18.118	18.391	0.2729
51	1e+13	NDD unbiased	19.367	18.535	-0.8327
52	1e+13	NDD unbiased	17.796	17.933	0.1361
53	1e+13	NDD unbiased	18.964	19.183	0.2186

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	18.804	19.287	19.77	0.68285	18.911	19.041	19.171	0.18321	-0.5996	-0.2463	0.107	0.49964
1e+12	18.277	18.958	19.871	0.66432	17.693	18.111	18.645	0.45888	-2.1775	-0.84722	0.0616	1.0107
5e+12	18.885	19.623	20.141	0.57988	17.772	18.293	19.034	0.61509	-2.3397	-1.3298	-0.8748	0.68023
1e+13	17.796	18.561	19.367	0.72888	17.933	18.51	19.183	0.5168	-0.8327	-0.051275	0.2729	0.52398

Device Test: 96.13 T_RLH_LARGE(_DLH Dead Time Large 2MHz VIN_12V)


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

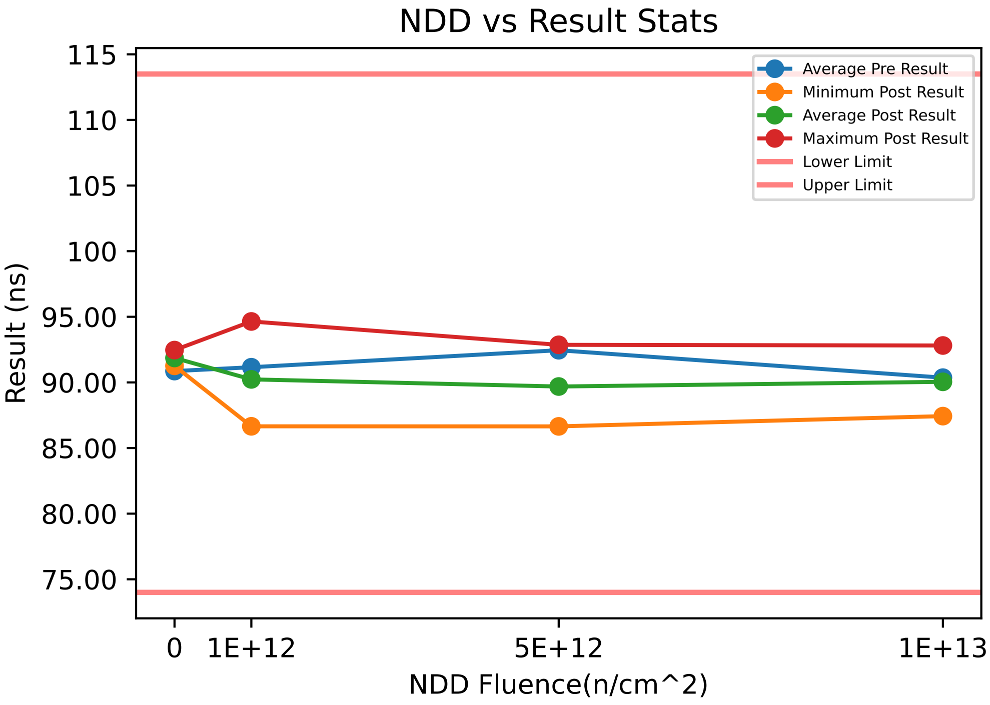
Test Results (Lower Limit = 36.0, Upper Limit = 59.0 (ns))

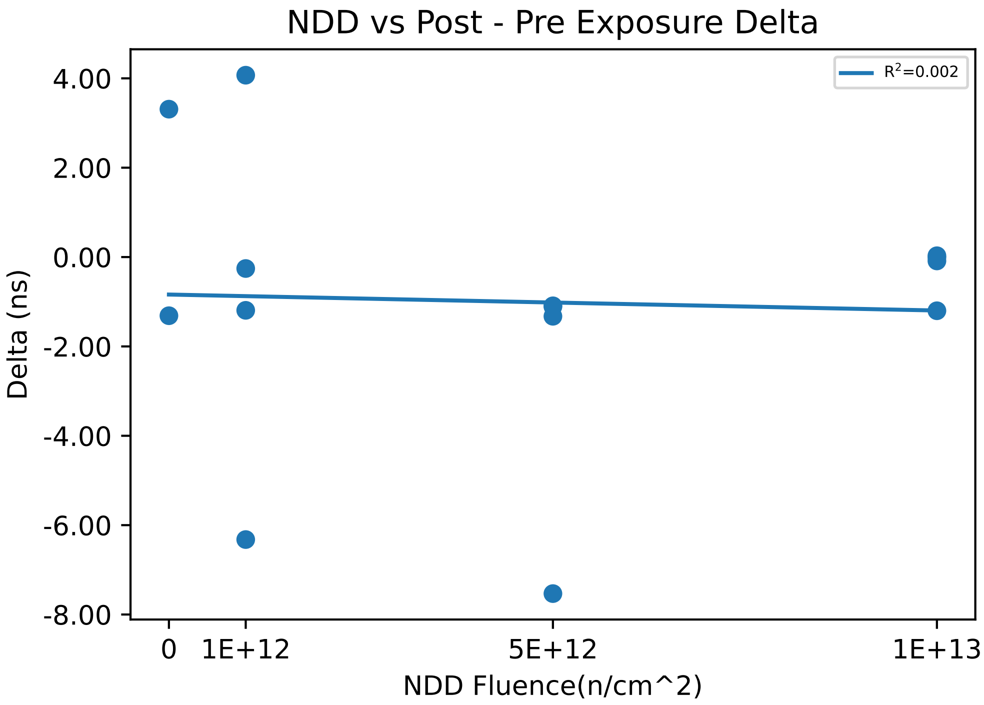
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	44.838	46.3	1.4621
2	0	Correlation	47.461	46.539	-0.9215
30	1e+12	NDD unbiased	44.933	46.279	1.3456
31	1e+12	NDD unbiased	47.329	43.621	-3.7079
32	1e+12	NDD unbiased	44.695	43.576	-1.1189
33	1e+12	NDD unbiased	46.9	46.821	-0.0793
44	5e+12	NDD unbiased	47.249	46.319	-0.9304
45	5e+12	NDD unbiased	47.761	43.609	-4.152
46	5e+12	NDD unbiased	47.648	46.739	-0.9093
47	5e+12	NDD unbiased	44.601	43.576	-1.0246
50	1e+13	NDD unbiased	46.015	45.928	-0.0878
51	1e+13	NDD unbiased	45.133	44.314	-0.8197
52	1e+13	NDD unbiased	43.996	44.034	0.0373
53	1e+13	NDD unbiased	46.655	46.731	0.0762

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	44.838	46.149	47.461	1.8547	46.3	46.42	46.539	0.16921	-0.9215	0.2703	1.4621	1.6855
1e+12	44.695	45.964	47.329	1.3432	43.576	45.074	46.821	1.7182	-3.7079	-0.89012	1.3456	2.1329
5e+12	44.601	46.815	47.761	1.4921	43.576	45.061	46.739	1.7039	-4.152	-1.7541	-0.9093	1.5994
1e+13	43.996	45.45	46.655	1.1526	44.034	45.252	46.731	1.2922	-0.8197	-0.1985	0.0762	0.42

Device Test: 96.14 T_RLH_MAX(_DLH Dead Time Max 2MHz VIN_12V)





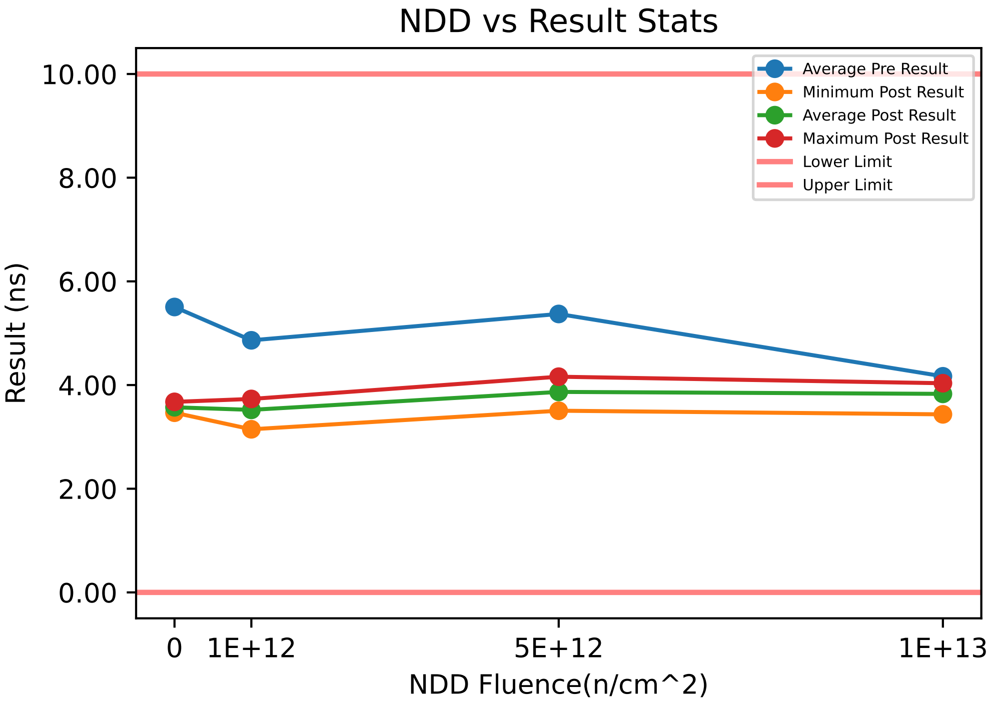
Test Results (Lower Limit = 74.0, Upper Limit = 113.5 (ns))

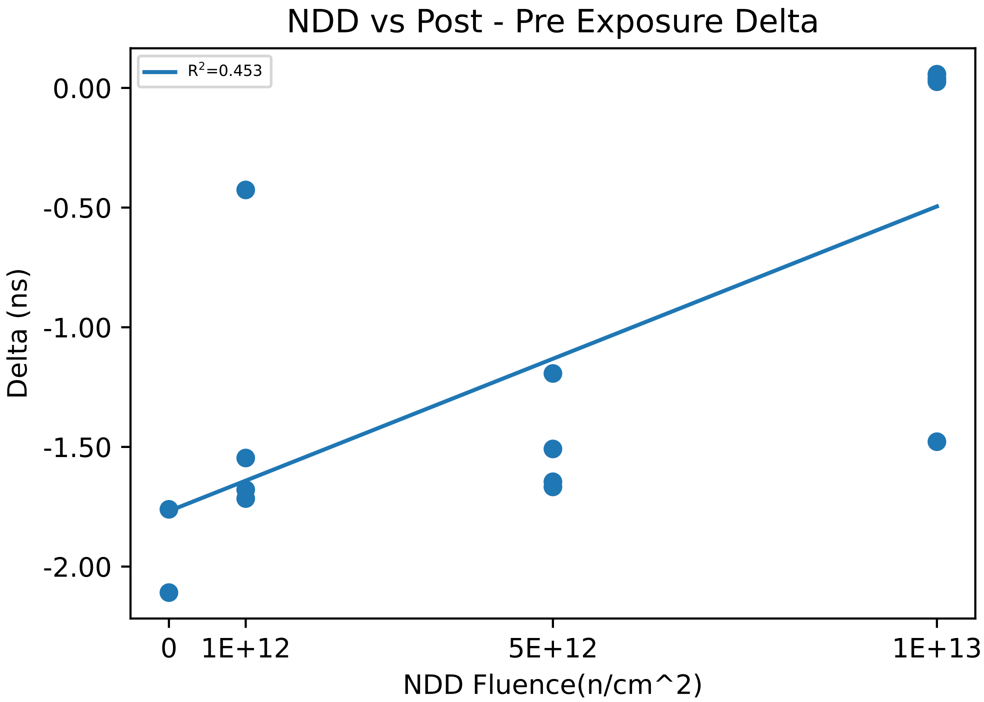
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	87.953	91.263	3.31
2	0	Correlation	93.776	92.463	-1.3128
30	1e+12	NDD unbiased	88.376	92.446	4.0702
31	1e+12	NDD unbiased	93.502	87.179	-6.3226
32	1e+12	NDD unbiased	87.847	86.655	-1.1923
33	1e+12	NDD unbiased	94.901	94.645	-0.2563
44	5e+12	NDD unbiased	93.677	92.586	-1.0912
45	5e+12	NDD unbiased	94.185	86.653	-7.5321
46	5e+12	NDD unbiased	93.973	92.864	-1.1088
47	5e+12	NDD unbiased	87.976	86.65	-1.3255
50	1e+13	NDD unbiased	91.894	91.807	-0.0866
51	1e+13	NDD unbiased	88.632	87.431	-1.2017
52	1e+13	NDD unbiased	88.141	88.129	-0.0119
53	1e+13	NDD unbiased	92.783	92.813	0.0295

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	87.953	90.864	93.776	4.1176	91.263	91.863	92.463	0.84881	-1.3128	0.9986	3.31	3.2688
1e+12	87.847	91.157	94.901	3.5687	86.655	90.231	94.645	3.9366	-6.3226	-0.92525	4.0702	4.2663
5e+12	87.976	92.452	94.185	2.9918	86.65	89.688	92.864	3.5084	-7.5321	-2.7644	-1.0912	3.1803
1e+13	88.141	90.363	92.783	2.319	87.431	90.045	92.813	2.6628	-1.2017	-0.31767	0.0295	0.5913

Device Test: 96.19 T_RHL_MIN(_DHL Dead Time Min 500kHz VIN_12V)


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

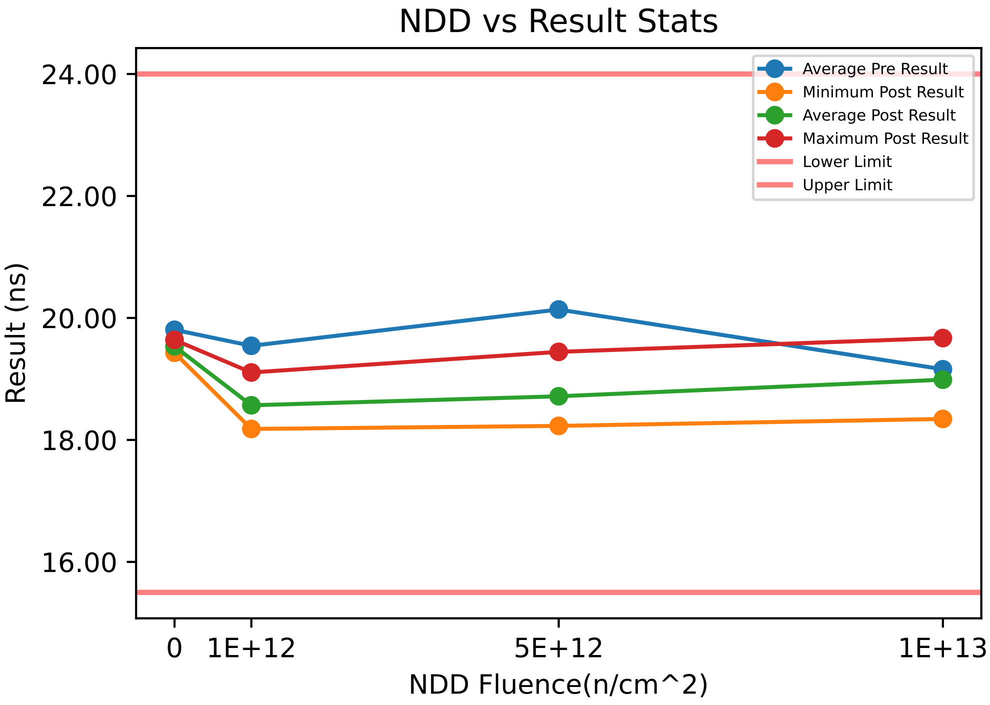
Test Results (Lower Limit = 0.0, Upper Limit = 10.0 (ns))

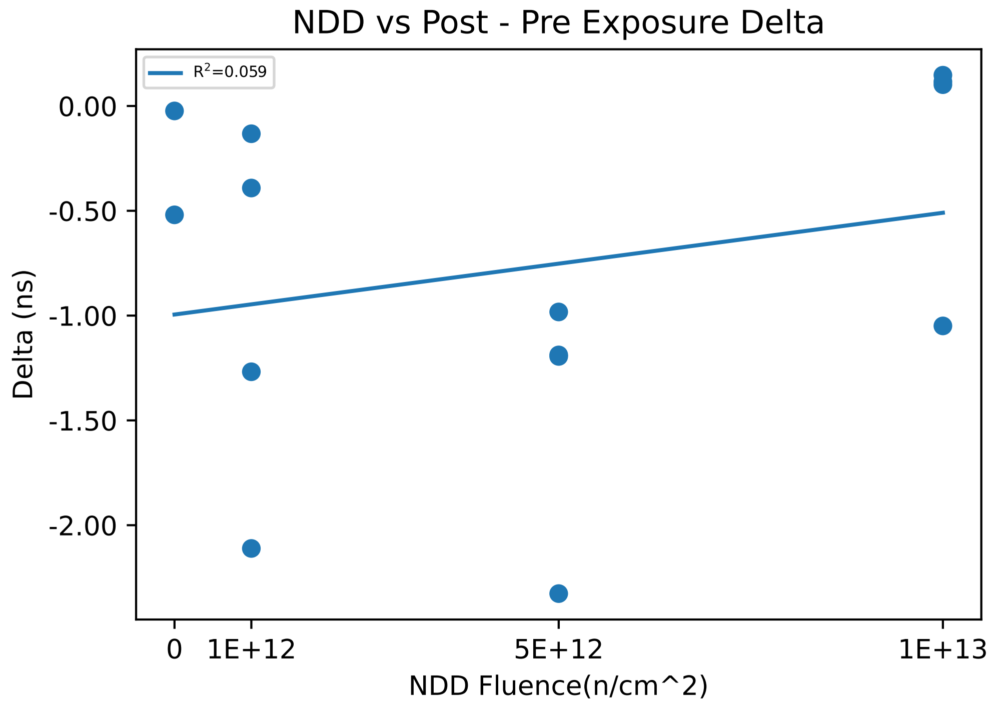
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	5.4362	3.6754	-1.7608
2	0	Correlation	5.5749	3.4662	-2.1087
30	1e+12	NDD unbiased	5.2229	3.5071	-1.7158
31	1e+12	NDD unbiased	5.2455	3.6992	-1.5463
32	1e+12	NDD unbiased	4.8249	3.1463	-1.6786
33	1e+12	NDD unbiased	4.158	3.7318	-0.4262
44	5e+12	NDD unbiased	5.8065	4.1609	-1.6456
45	5e+12	NDD unbiased	5.0721	3.879	-1.1931
46	5e+12	NDD unbiased	5.1718	3.5047	-1.6671
47	5e+12	NDD unbiased	5.434	3.9255	-1.5085
50	1e+13	NDD unbiased	3.3773	3.4347	0.0574
51	1e+13	NDD unbiased	5.5131	4.0349	-1.4782
52	1e+13	NDD unbiased	3.9279	3.9671	0.0392
53	1e+13	NDD unbiased	3.8563	3.8822	0.0259

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.4362	5.5056	5.5749	0.098076	3.4662	3.5708	3.6754	0.14793	-2.1087	-1.9348	-1.7608	0.246
1e+12	4.158	4.8628	5.2455	0.50804	3.1463	3.5211	3.7318	0.26882	-1.7158	-1.3417	-0.4262	0.61467
5e+12	5.0721	5.3711	5.8065	0.32795	3.5047	3.8675	4.1609	0.27154	-1.6671	-1.5036	-1.1931	0.21858
1e+13	3.3773	4.1686	5.5131	0.92903	3.4347	3.8297	4.0349	0.27066	-1.4782	-0.33892	0.0574	0.75963

Device Test: 96.2 T_RLH_MID(_DLH Dead Time Mid 500kHz VIN_12V)


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

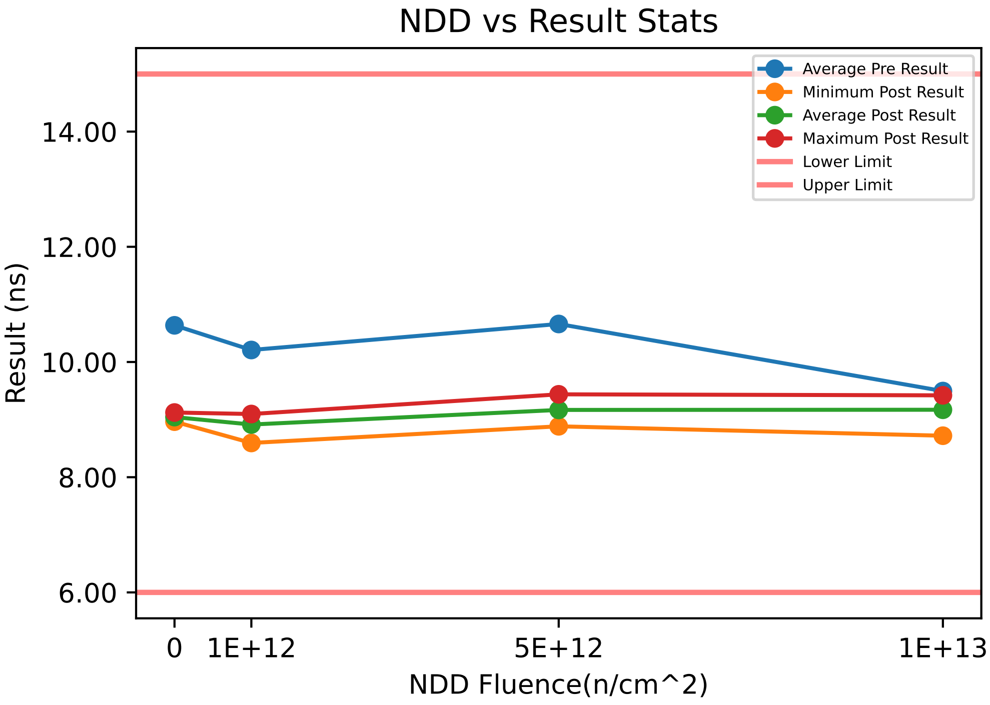
Test Results (Lower Limit = 15.5, Upper Limit = 24.0 (ns))

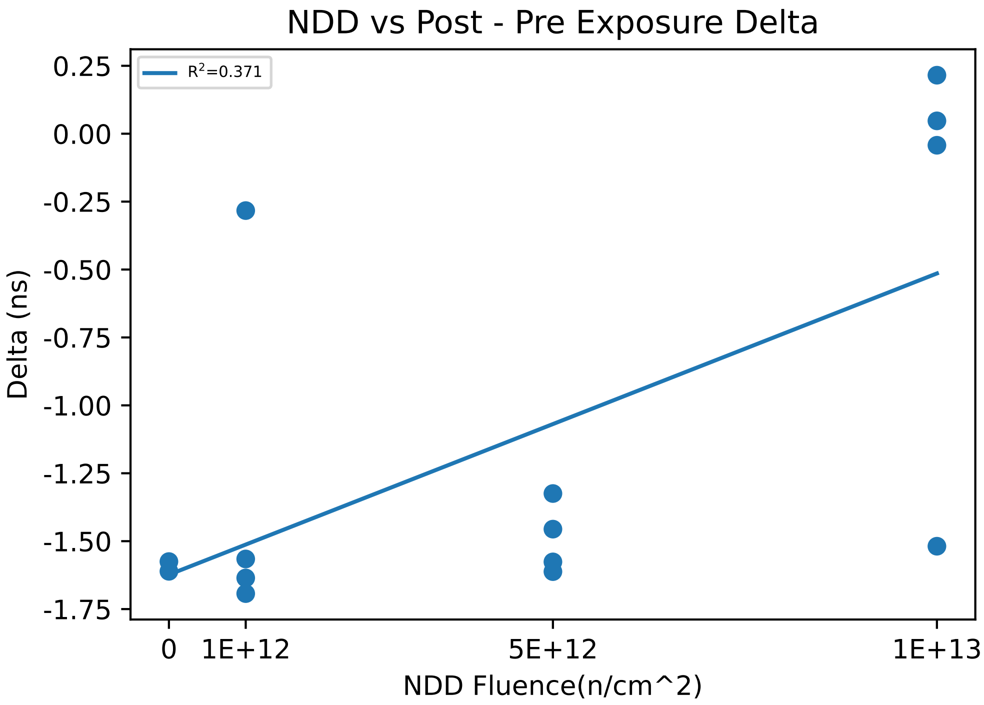
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	19.453	19.429	-0.0236
2	0	Correlation	20.16	19.64	-0.5193
30	1e+12	NDD unbiased	19.497	19.106	-0.3913
31	1e+12	NDD unbiased	20.356	18.245	-2.1109
32	1e+12	NDD unbiased	19.448	18.18	-1.268
33	1e+12	NDD unbiased	18.873	18.74	-0.1324
44	5e+12	NDD unbiased	19.888	18.905	-0.9826
45	5e+12	NDD unbiased	20.609	18.283	-2.3263
46	5e+12	NDD unbiased	20.639	19.444	-1.1948
47	5e+12	NDD unbiased	19.418	18.23	-1.1876
50	1e+13	NDD unbiased	18.807	18.909	0.1017
51	1e+13	NDD unbiased	20.076	19.027	-1.0492
52	1e+13	NDD unbiased	18.228	18.344	0.1161
53	1e+13	NDD unbiased	19.523	19.67	0.1469

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	19.453	19.806	20.16	0.49971	19.429	19.535	19.64	0.1492	-0.5193	-0.27145	-0.0236	0.35051
1e+12	18.873	19.544	20.356	0.61144	18.18	18.568	19.106	0.43736	-2.1109	-0.97565	-0.1324	0.89941
5e+12	19.418	20.138	20.639	0.59275	18.23	18.716	19.444	0.57434	-2.3263	-1.4228	-0.9826	0.6103
1e+13	18.228	19.159	20.076	0.80939	18.344	18.988	19.67	0.54407	-1.0492	-0.17112	0.1469	0.58569

Device Test: 96.20 T_RHL_SMALL(_DHL Dead Time Small 500kHz VIN_12V)





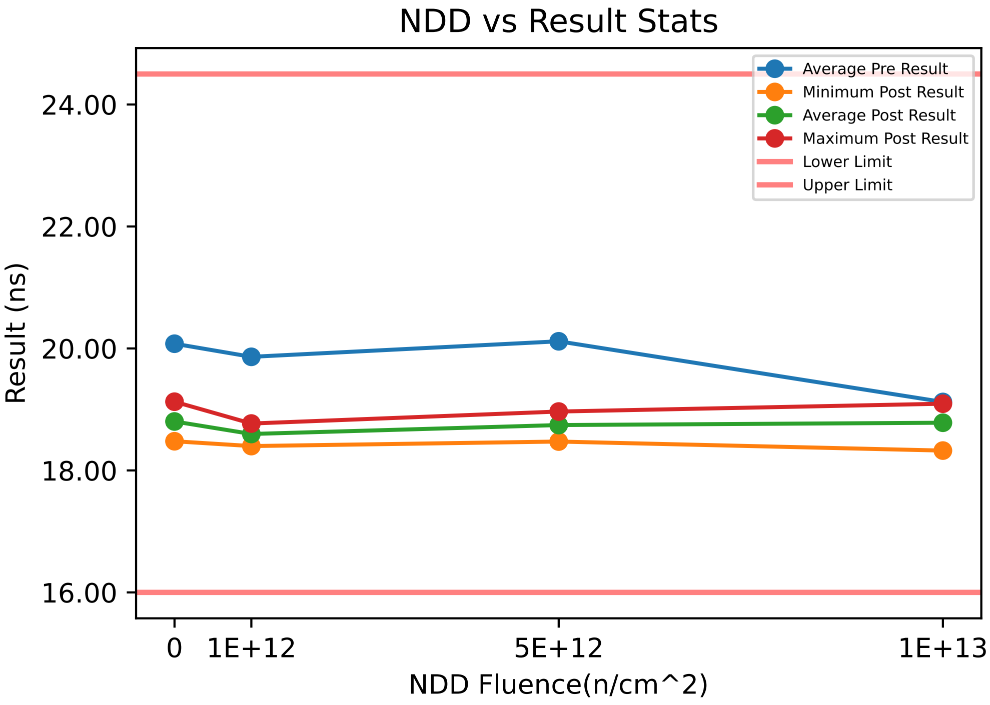
Test Results (Lower Limit = 6.0, Upper Limit = 15.0 (ns))

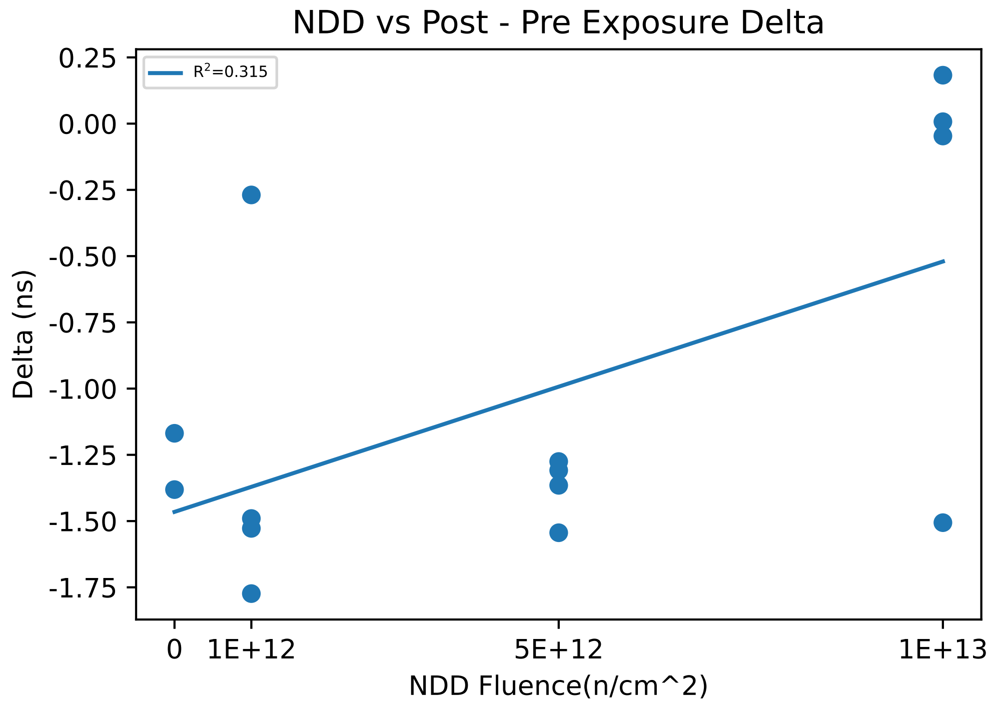
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	10.575	8.9642	-1.611
2	0	Correlation	10.698	9.1229	-1.5751
30	1e+12	NDD unbiased	10.575	9.0094	-1.5655
31	1e+12	NDD unbiased	10.649	8.9562	-1.693
32	1e+12	NDD unbiased	10.23	8.5945	-1.6355
33	1e+12	NDD unbiased	9.3799	9.0969	-0.283
44	5e+12	NDD unbiased	11.015	9.4388	-1.5763
45	5e+12	NDD unbiased	10.466	9.1415	-1.3246
46	5e+12	NDD unbiased	10.496	8.8835	-1.6121
47	5e+12	NDD unbiased	10.664	9.2078	-1.4557
50	1e+13	NDD unbiased	8.673	8.7203	0.0473
51	1e+13	NDD unbiased	10.94	9.4213	-1.5186
52	1e+13	NDD unbiased	9.3352	9.2927	-0.0425
53	1e+13	NDD unbiased	9.0337	9.2491	0.2154

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	10.575	10.637	10.698	0.086833	8.9642	9.0435	9.1229	0.11222	-1.611	-1.5931	-1.5751	0.025385
1e+12	9.3799	10.209	10.649	0.58181	8.5945	8.9142	9.0969	0.22092	-1.693	-1.2942	-0.283	0.67618
5e+12	10.466	10.66	11.015	0.25215	8.8835	9.1679	9.4388	0.22844	-1.6121	-1.4922	-1.3246	0.13022
1e+13	8.673	9.4954	10.94	1.0003	8.7203	9.1708	9.4213	0.30913	-1.5186	-0.3246	0.2154	0.80315

Device Test: 96.21 T_RHL_MID(_DHL Dead Time Mid 500kHz VIN_12V)


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

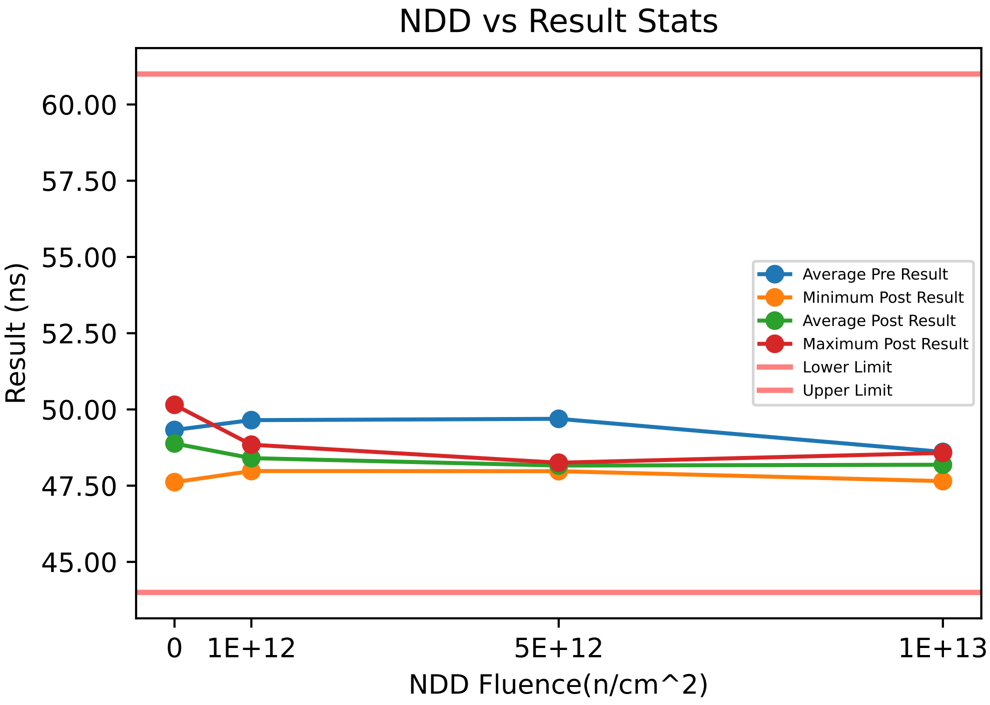
Test Results (Lower Limit = 16.0, Upper Limit = 24.5 (ns))

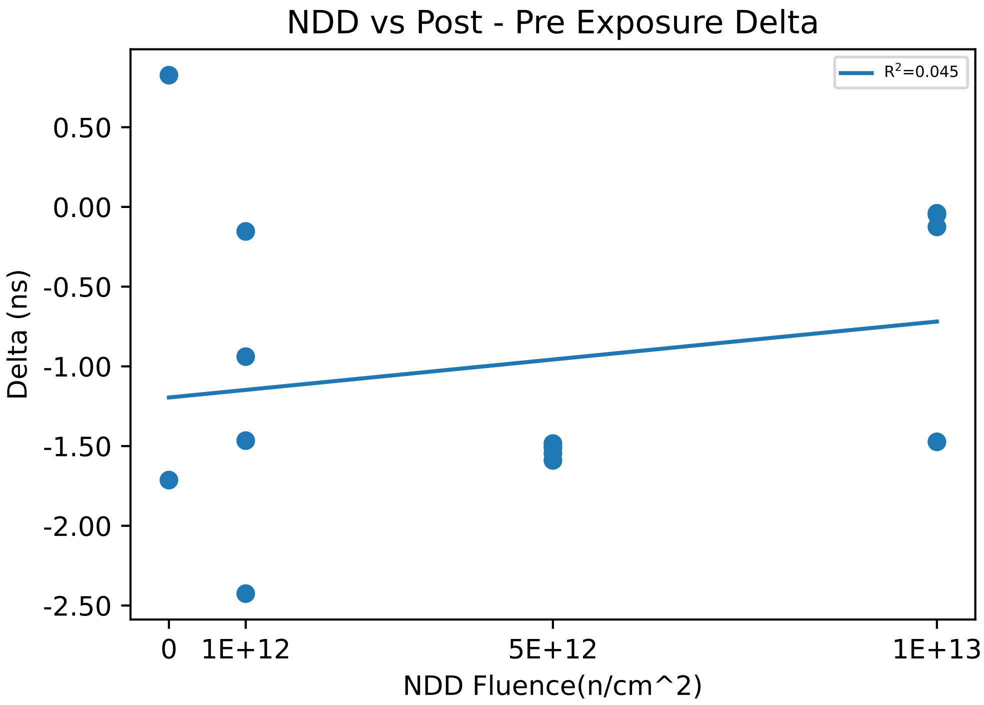
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	19.86	18.478	-1.3812
2	0	Correlation	20.295	19.127	-1.1687
30	1e+12	NDD unbiased	20.259	18.769	-1.4903
31	1e+12	NDD unbiased	20.374	18.601	-1.7737
32	1e+12	NDD unbiased	19.927	18.399	-1.5275
33	1e+12	NDD unbiased	18.89	18.621	-0.2691
44	5e+12	NDD unbiased	20.274	18.966	-1.3086
45	5e+12	NDD unbiased	20.005	18.73	-1.2752
46	5e+12	NDD unbiased	20.017	18.473	-1.544
47	5e+12	NDD unbiased	20.171	18.806	-1.3651
50	1e+13	NDD unbiased	18.142	18.325	0.1828
51	1e+13	NDD unbiased	20.6	19.094	-1.506
52	1e+13	NDD unbiased	18.971	18.924	-0.0467
53	1e+13	NDD unbiased	18.777	18.784	0.0073

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	19.86	20.077	20.295	0.30823	18.478	18.803	19.127	0.45849	-1.3812	-1.275	-1.1687	0.15026
1e+12	18.89	19.863	20.374	0.67538	18.399	18.598	18.769	0.15192	-1.7737	-1.2652	-0.2691	0.67583
5e+12	20.005	20.117	20.274	0.12914	18.473	18.744	18.966	0.20526	-1.544	-1.3732	-1.2752	0.11974
1e+13	18.142	19.123	20.6	1.0465	18.325	18.782	19.094	0.32972	-1.506	-0.34065	0.1828	0.78305

Device Test: 96.22 T_RHL_LARGE(_DHL Dead Time Large 500kHz VIN_12V)





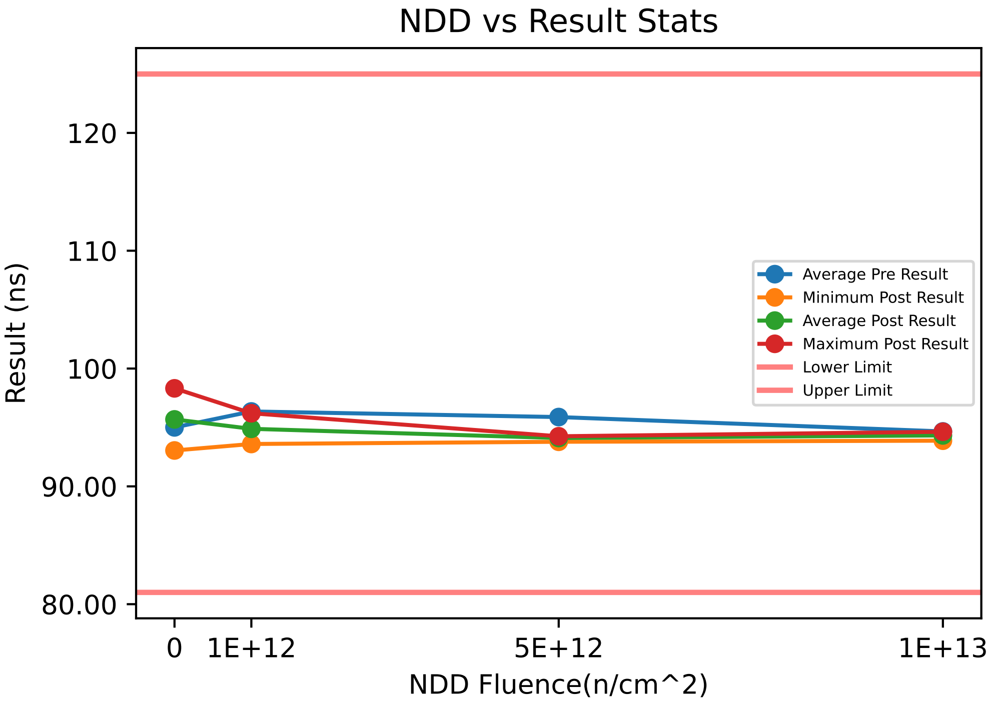
Test Results (Lower Limit = 44.0, Upper Limit = 61.0 (ns))

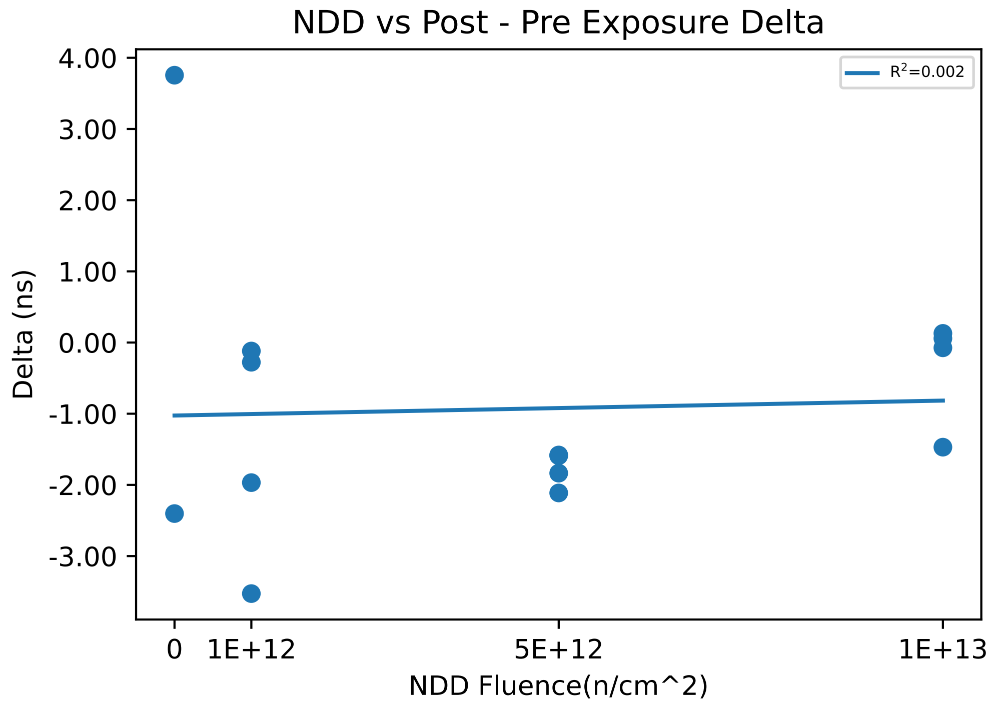
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	49.329	47.615	-1.7134
2	0	Correlation	49.325	50.151	0.8263
30	1e+12	NDD unbiased	49.783	48.844	-0.939
31	1e+12	NDD unbiased	50.542	48.116	-2.4253
32	1e+12	NDD unbiased	50.138	48.672	-1.4657
33	1e+12	NDD unbiased	48.133	47.979	-0.1537
44	5e+12	NDD unbiased	49.736	48.228	-1.5078
45	5e+12	NDD unbiased	49.668	48.184	-1.4841
46	5e+12	NDD unbiased	49.521	47.975	-1.5459
47	5e+12	NDD unbiased	49.843	48.253	-1.5901
50	1e+13	NDD unbiased	47.696	47.649	-0.0474
51	1e+13	NDD unbiased	50.048	48.574	-1.4734
52	1e+13	NDD unbiased	48.457	48.332	-0.1253
53	1e+13	NDD unbiased	48.23	48.19	-0.0398

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	49.325	49.327	49.329	0.0024749	47.615	48.883	50.151	1.7934	-1.7134	-0.44355	0.8263	1.7958
1e+12	48.133	49.649	50.542	1.057	47.979	48.403	48.844	0.41976	-2.4253	-1.2459	-0.1537	0.95331
5e+12	49.521	49.692	49.843	0.1348	47.975	48.16	48.253	0.12654	-1.5901	-1.532	-1.4841	0.046364
1e+13	47.696	48.608	50.048	1.0115	47.649	48.186	48.574	0.39178	-1.4734	-0.42148	-0.0398	0.70235

Device Test: 96.23 T_RHL_MAX(_DHL Dead Time Max 500kHz VIN_12V)





Test Results (Lower Limit = 81.0, Upper Limit = 125.0 (ns))

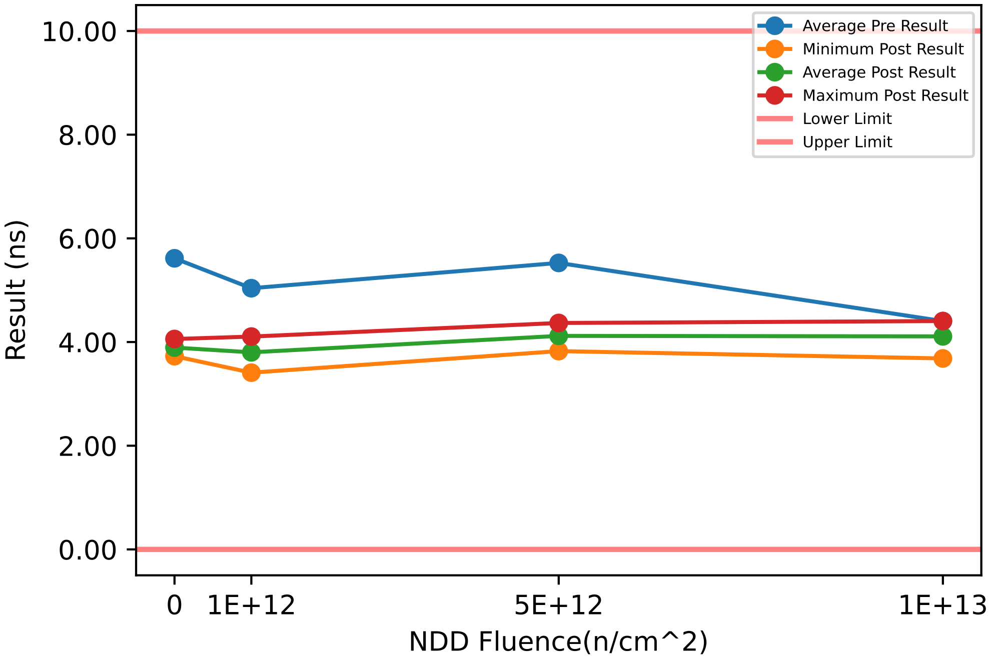
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	95.449	93.046	-2.4026
2	0	Correlation	94.564	98.319	3.7556
30	1e+12	NDD unbiased	95.906	95.629	-0.2767
31	1e+12	NDD unbiased	97.632	94.105	-3.5269
32	1e+12	NDD unbiased	98.174	96.206	-1.9679
33	1e+12	NDD unbiased	93.716	93.597	-0.1192
44	5e+12	NDD unbiased	95.62	93.785	-1.835
45	5e+12	NDD unbiased	96.364	94.251	-2.113
46	5e+12	NDD unbiased	95.704	94.124	-1.5798
47	5e+12	NDD unbiased	95.841	94.251	-1.59
50	1e+13	NDD unbiased	93.747	93.876	0.1287
51	1e+13	NDD unbiased	96.014	94.544	-1.4698
52	1e+13	NDD unbiased	94.315	94.241	-0.0741
53	1e+13	NDD unbiased	94.576	94.634	0.0579

Test Statistics (ns)

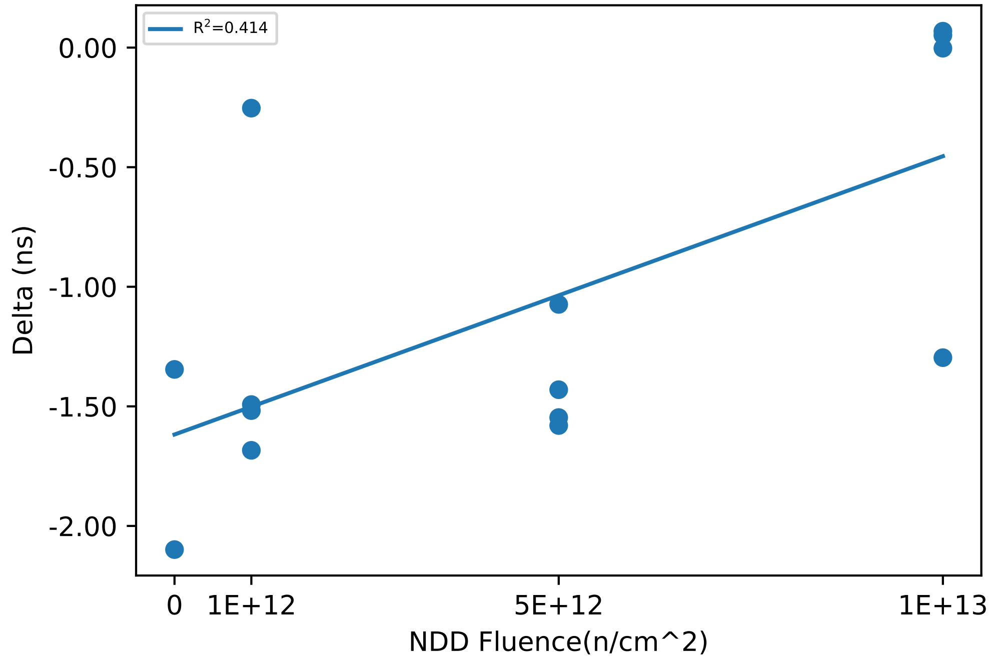
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	94.564	95.006	95.449	0.62586	93.046	95.683	98.319	3.7286	-2.4026	0.6765	3.7556	4.3545
1e+12	93.716	96.357	98.174	2.0086	93.597	94.884	96.206	1.2338	-3.5269	-1.4727	-0.1192	1.6049
5e+12	95.62	95.882	96.364	0.3341	93.785	94.103	94.251	0.22036	-2.113	-1.7795	-1.5798	0.25172
1e+13	93.747	94.663	96.014	0.96481	93.876	94.324	94.634	0.34259	-1.4698	-0.33933	0.1287	0.75832

Device Test: 96.24 T_RHL_MIN(_DHL Dead Time Min 1MHz VIN_12V)

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



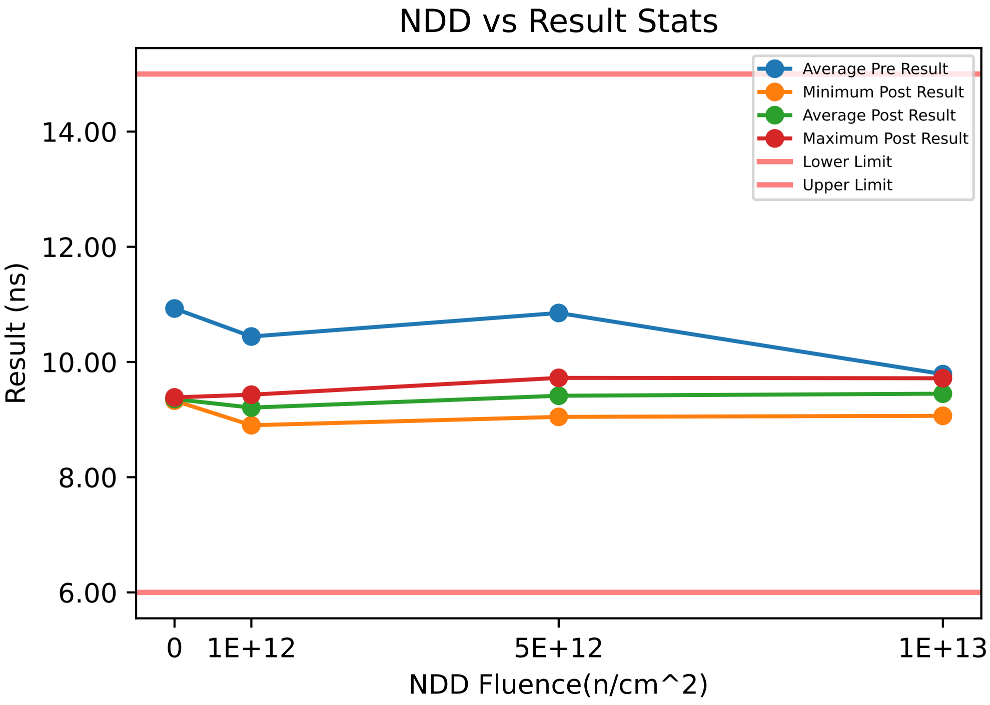
Test Results (Lower Limit = 0.0, Upper Limit = 10.0 (ns))

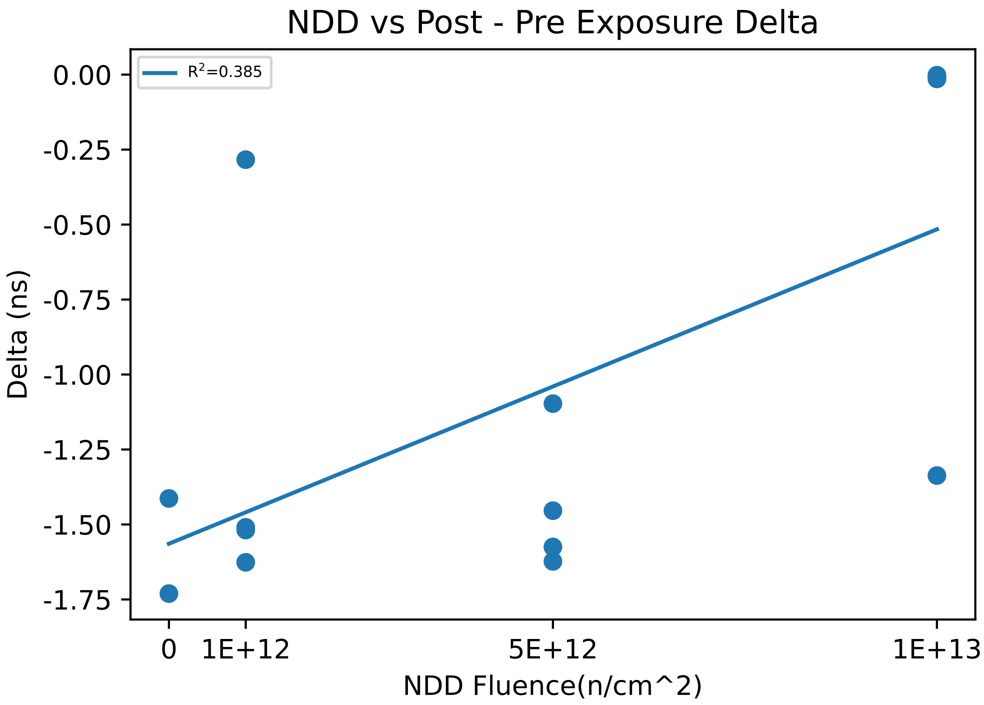
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	5.4041	4.0586	-1.3455
2	0	Correlation	5.8264	3.7275	-2.0989
30	1e+12	NDD unbiased	5.4427	3.7589	-1.6838
31	1e+12	NDD unbiased	5.4506	3.9329	-1.5177
32	1e+12	NDD unbiased	4.902	3.4095	-1.4925
33	1e+12	NDD unbiased	4.3584	4.1053	-0.2531
44	5e+12	NDD unbiased	5.9146	4.3678	-1.5468
45	5e+12	NDD unbiased	5.242	4.1683	-1.0737
46	5e+12	NDD unbiased	5.2553	3.8249	-1.4304
47	5e+12	NDD unbiased	5.6935	4.1134	-1.5801
50	1e+13	NDD unbiased	3.6318	3.6836	0.0518
51	1e+13	NDD unbiased	5.7012	4.4048	-1.2964
52	1e+13	NDD unbiased	4.246	4.2435	-0.0025
53	1e+13	NDD unbiased	4.0358	4.1044	0.0686

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.4041	5.6152	5.8264	0.29861	3.7275	3.8931	4.0586	0.23412	-2.0989	-1.7222	-1.3455	0.53273
1e+12	4.3584	5.0384	5.4506	0.52102	3.4095	3.8016	4.1053	0.29723	-1.6838	-1.2368	-0.2531	0.66125
5e+12	5.242	5.5263	5.9146	0.33317	3.8249	4.1186	4.3678	0.22424	-1.5801	-1.4078	-1.0737	0.23176
1e+13	3.6318	4.4037	5.7012	0.90177	3.6836	4.1091	4.4048	0.30907	-1.2964	-0.29463	0.0686	0.66854

Device Test: 96.25 T_RHL_SMALL(_DHL Dead Time Small 1MHz VIN_12V)





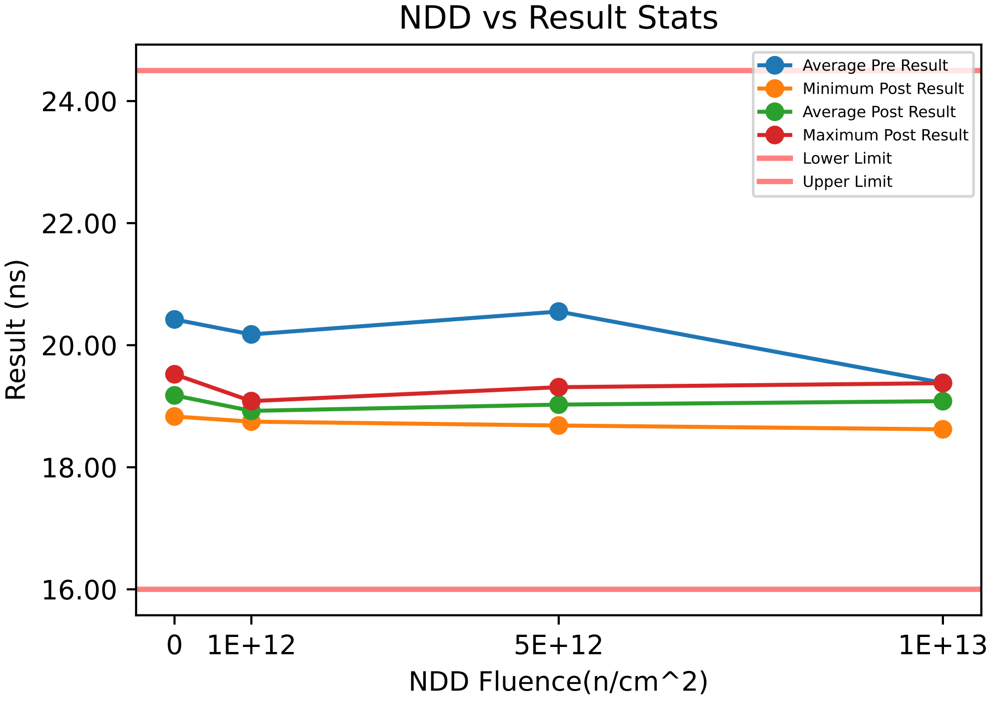
Test Results (Lower Limit = 6.0, Upper Limit = 15.0 (ns))

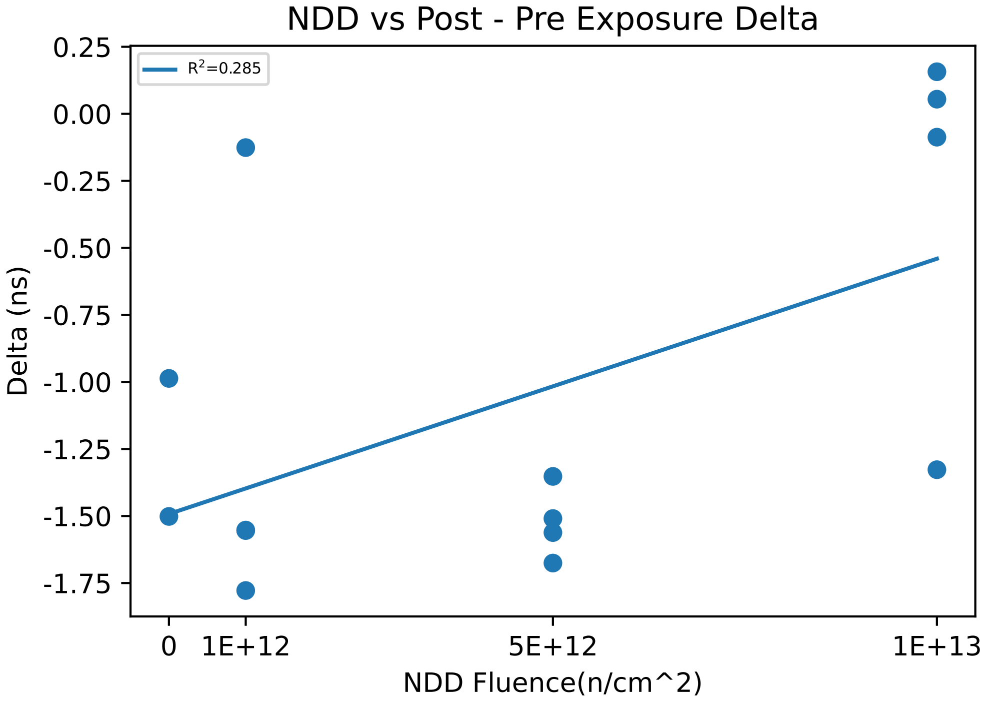
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	10.742	9.3284	-1.4132
2	0	Correlation	11.116	9.3853	-1.7305
30	1e+12	NDD unbiased	10.729	9.2194	-1.5095
31	1e+12	NDD unbiased	10.905	9.2786	-1.6262
32	1e+12	NDD unbiased	10.42	8.9017	-1.5185
33	1e+12	NDD unbiased	9.7161	9.4325	-0.2836
44	5e+12	NDD unbiased	11.178	9.7245	-1.454
45	5e+12	NDD unbiased	10.549	9.4515	-1.097
46	5e+12	NDD unbiased	10.67	9.0473	-1.6231
47	5e+12	NDD unbiased	11.008	9.4327	-1.575
50	1e+13	NDD unbiased	9.0795	9.0653	-0.0142
51	1e+13	NDD unbiased	11.055	9.7179	-1.3369
52	1e+13	NDD unbiased	9.6064	9.6045	-0.0019
53	1e+13	NDD unbiased	9.4169	9.4112	-0.0057

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	10.742	10.929	11.116	0.2646	9.3284	9.3569	9.3853	0.040234	-1.7305	-1.5718	-1.4132	0.22436
1e+12	9.7161	10.442	10.905	0.52405	8.9017	9.2081	9.4325	0.22311	-1.6262	-1.2344	-0.2836	0.63611
5e+12	10.549	10.851	11.178	0.29208	9.0473	9.414	9.7245	0.27847	-1.6231	-1.4373	-1.097	0.23774
1e+13	9.0795	9.7894	11.055	0.87129	9.0653	9.4497	9.7179	0.28586	-1.3369	-0.33968	-0.0019	0.66484

Device Test: 96.26 T_RHL_MID(_DHL Dead Time Mid 1MHz VIN_12V)


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

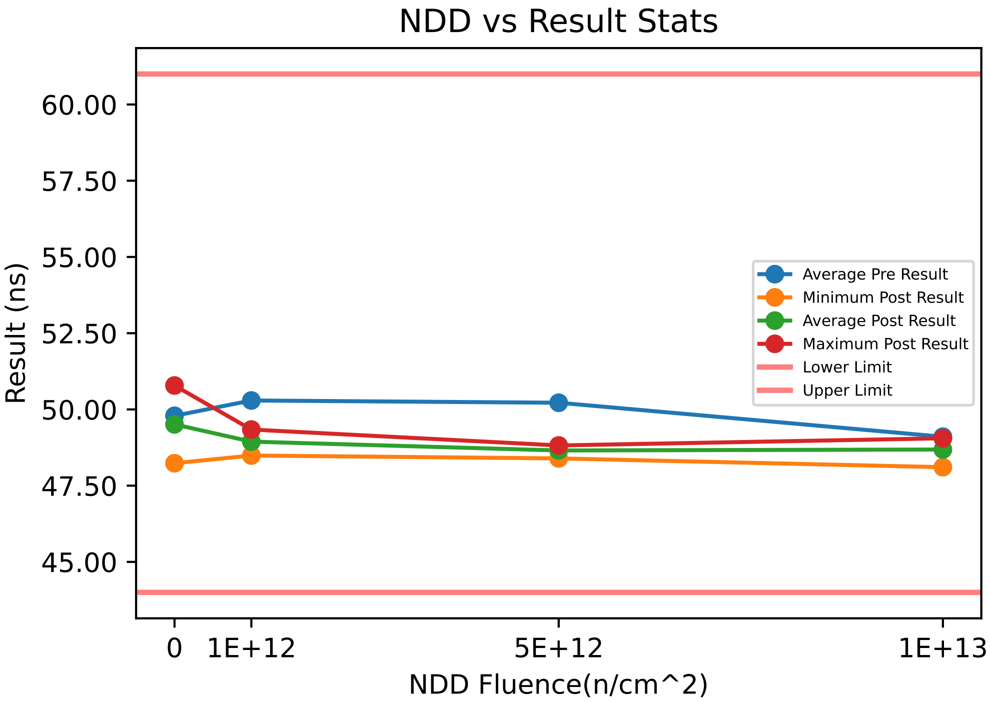
Test Results (Lower Limit = 16.0, Upper Limit = 24.5 (ns))

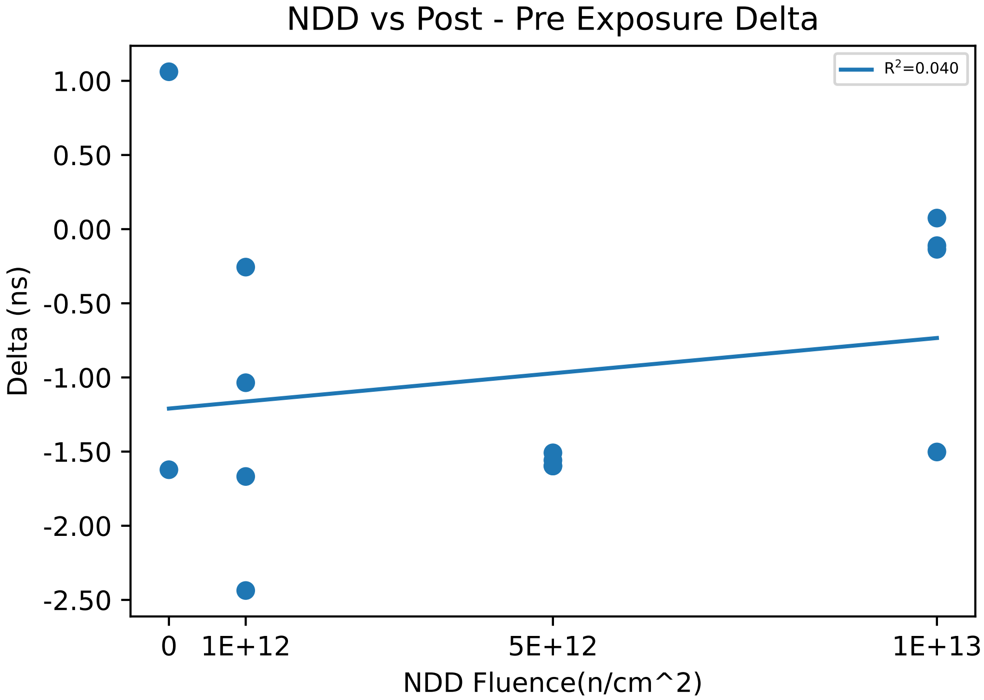
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	20.333	18.832	-1.5016
2	0	Correlation	20.51	19.523	-0.9868
30	1e+12	NDD unbiased	20.637	19.084	-1.5525
31	1e+12	NDD unbiased	20.684	18.907	-1.7779
32	1e+12	NDD unbiased	20.302	18.748	-1.5543
33	1e+12	NDD unbiased	19.083	18.957	-0.126
44	5e+12	NDD unbiased	20.821	19.312	-1.5095
45	5e+12	NDD unbiased	20.421	19.069	-1.3523
46	5e+12	NDD unbiased	20.36	18.684	-1.6755
47	5e+12	NDD unbiased	20.603	19.041	-1.5618
50	1e+13	NDD unbiased	18.709	18.622	-0.0871
51	1e+13	NDD unbiased	20.705	19.378	-1.3273
52	1e+13	NDD unbiased	19.108	19.265	0.1569
53	1e+13	NDD unbiased	19.011	19.066	0.0546

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	20.333	20.422	20.51	0.12502	18.832	19.178	19.523	0.48904	-1.5016	-1.2442	-0.9868	0.36402
1e+12	19.083	20.177	20.684	0.74849	18.748	18.924	19.084	0.13915	-1.7779	-1.2527	-0.126	0.75854
5e+12	20.36	20.551	20.821	0.20764	18.684	19.026	19.312	0.25856	-1.6755	-1.5248	-1.3523	0.13425
1e+13	18.709	19.383	20.705	0.89751	18.622	19.082	19.378	0.3332	-1.3273	-0.30072	0.1569	0.69166

Device Test: 96.27 T_RHL_LARGE(_DHL Dead Time Large 1MHz VIN_12V)





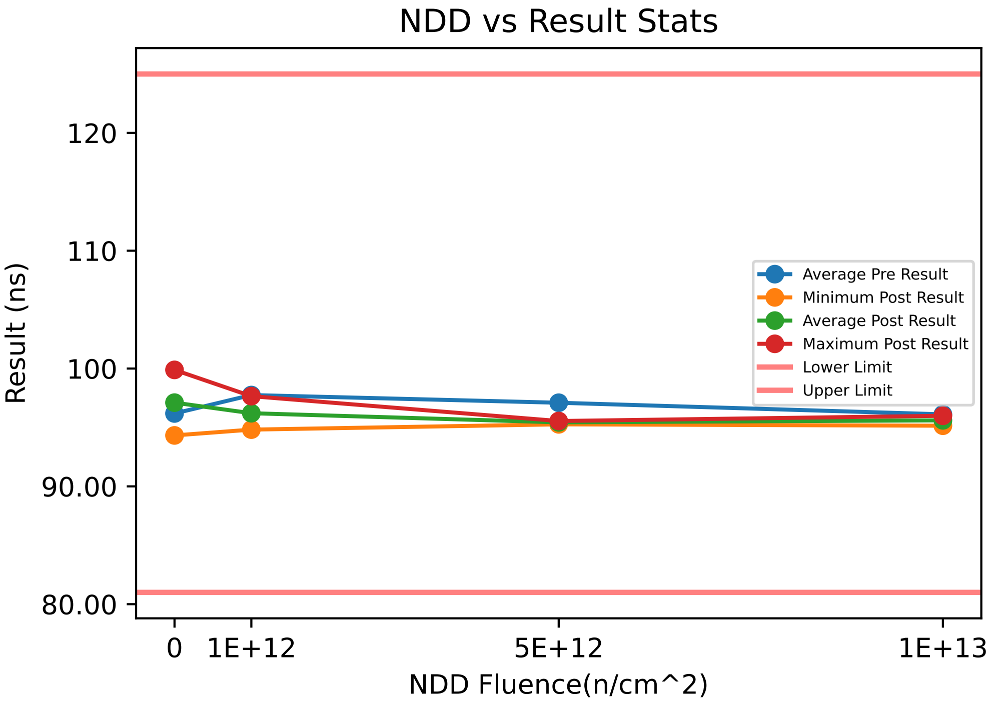
Test Results (Lower Limit = 44.0, Upper Limit = 61.0 (ns))

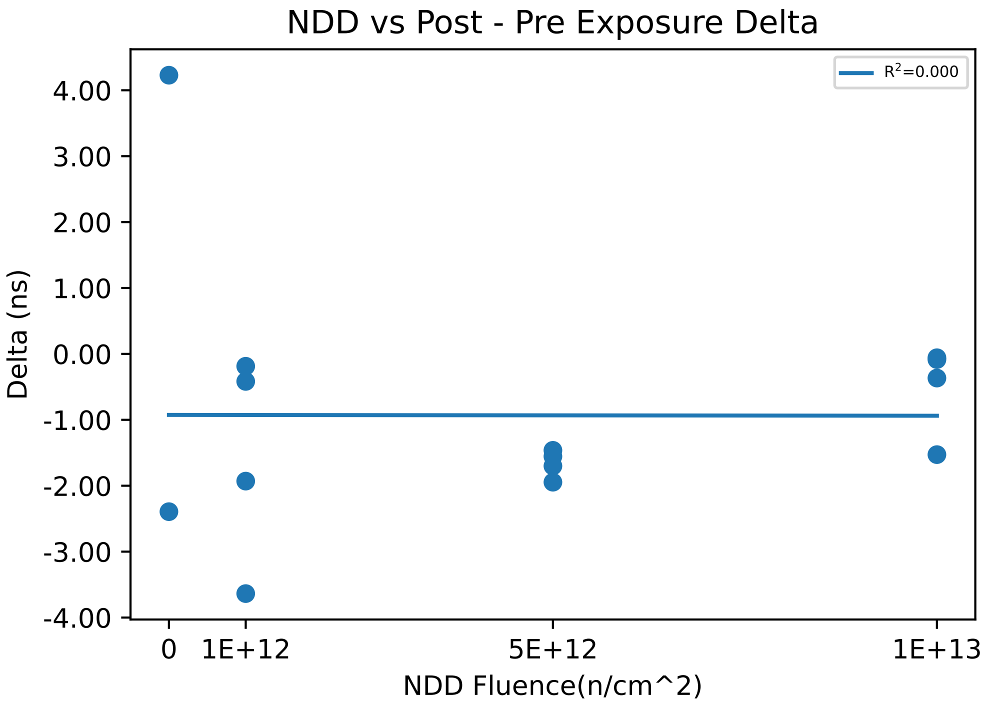
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	49.858	48.236	-1.6222
2	0	Correlation	49.724	50.785	1.0613
30	1e+12	NDD unbiased	50.376	49.341	-1.0355
31	1e+12	NDD unbiased	51.099	48.662	-2.4367
32	1e+12	NDD unbiased	50.955	49.287	-1.6678
33	1e+12	NDD unbiased	48.744	48.488	-0.256
44	5e+12	NDD unbiased	50.377	48.819	-1.5584
45	5e+12	NDD unbiased	50.299	48.703	-1.5968
46	5e+12	NDD unbiased	49.991	48.394	-1.5972
47	5e+12	NDD unbiased	50.211	48.702	-1.5083
50	1e+13	NDD unbiased	48.242	48.106	-0.1361
51	1e+13	NDD unbiased	50.556	49.054	-1.5025
52	1e+13	NDD unbiased	48.971	48.86	-0.1112
53	1e+13	NDD unbiased	48.649	48.724	0.0747

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	49.724	49.791	49.858	0.094964	48.236	49.511	50.785	1.8026	-1.6222	-0.28045	1.0613	1.8975
1e+12	48.744	50.294	51.099	1.0789	48.488	48.945	49.341	0.43297	-2.4367	-1.349	-0.256	0.92694
5e+12	49.991	50.22	50.377	0.16671	48.394	48.654	48.819	0.18201	-1.5972	-1.5652	-1.5083	0.042057
1e+13	48.242	49.105	50.556	1.0125	48.106	48.686	49.054	0.40942	-1.5025	-0.41878	0.0747	0.72858

Device Test: 96.28 T_RHL_MAX(_DHL Dead Time Max 1MHz VIN_12V)





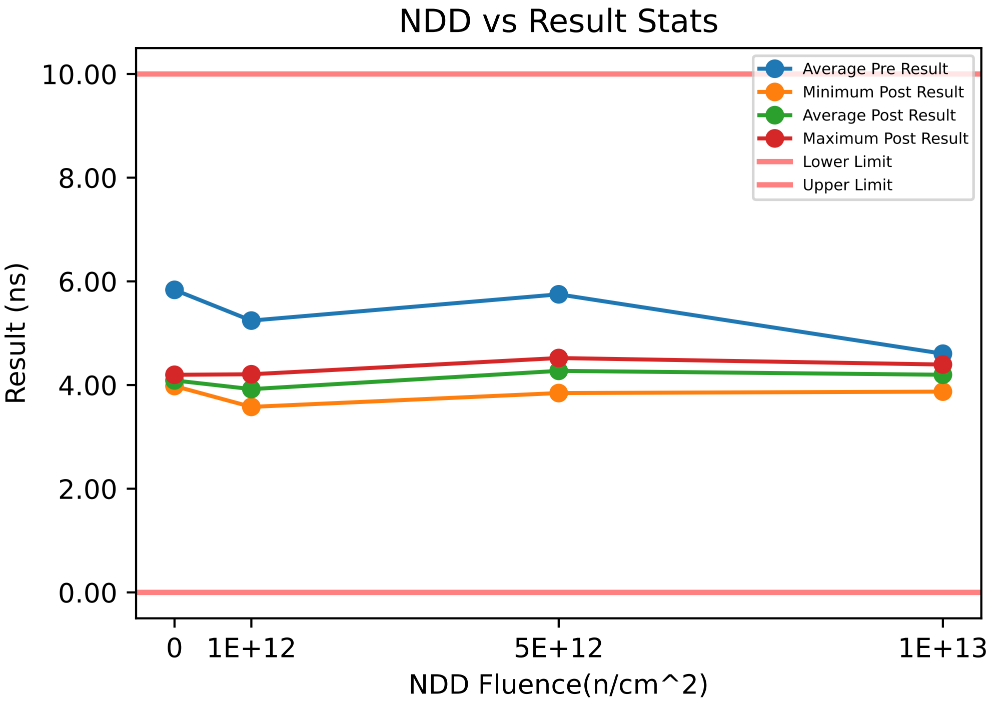
Test Results (Lower Limit = 81.0, Upper Limit = 125.0 (ns))

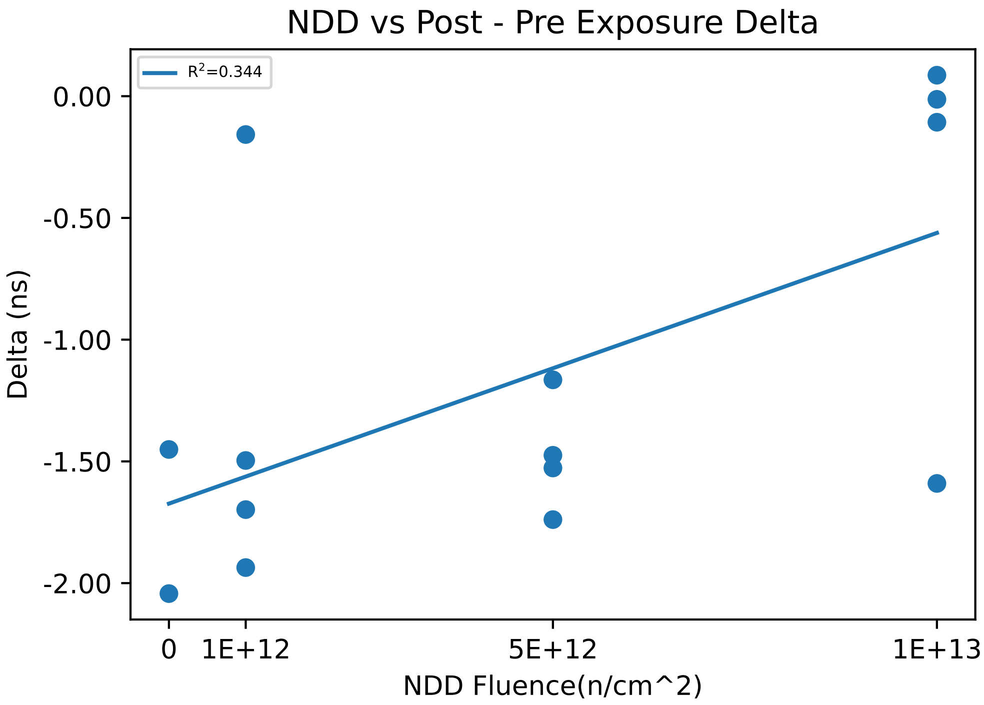
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	96.717	94.324	-2.3934
2	0	Correlation	95.658	99.887	4.2284
30	1e+12	NDD unbiased	97.144	96.957	-0.1872
31	1e+12	NDD unbiased	99.04	95.404	-3.6363
32	1e+12	NDD unbiased	99.585	97.655	-1.9299
33	1e+12	NDD unbiased	95.234	94.817	-0.4173
44	5e+12	NDD unbiased	96.727	95.264	-1.4628
45	5e+12	NDD unbiased	97.49	95.544	-1.9463
46	5e+12	NDD unbiased	97.073	95.372	-1.7004
47	5e+12	NDD unbiased	97.101	95.547	-1.5545
50	1e+13	NDD unbiased	95.233	95.147	-0.0857
51	1e+13	NDD unbiased	97.338	95.81	-1.528
52	1e+13	NDD unbiased	95.834	95.468	-0.3664
53	1e+13	NDD unbiased	96.049	95.991	-0.0582

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	95.658	96.188	96.717	0.74883	94.324	97.105	99.887	3.9335	-2.3934	0.9175	4.2284	4.6823
1e+12	95.234	97.751	99.585	1.9774	94.817	96.208	97.655	1.3211	-3.6363	-1.5427	-0.1872	1.5955
5e+12	96.727	97.098	97.49	0.31192	95.264	95.432	95.547	0.13823	-1.9463	-1.666	-1.4628	0.21093
1e+13	95.233	96.114	97.338	0.88642	95.147	95.604	95.991	0.37378	-1.528	-0.50958	-0.0582	0.69308

Device Test: 96.29 T_RHL_MIN(_DHL Dead Time Min 2MHz VIN_12V)





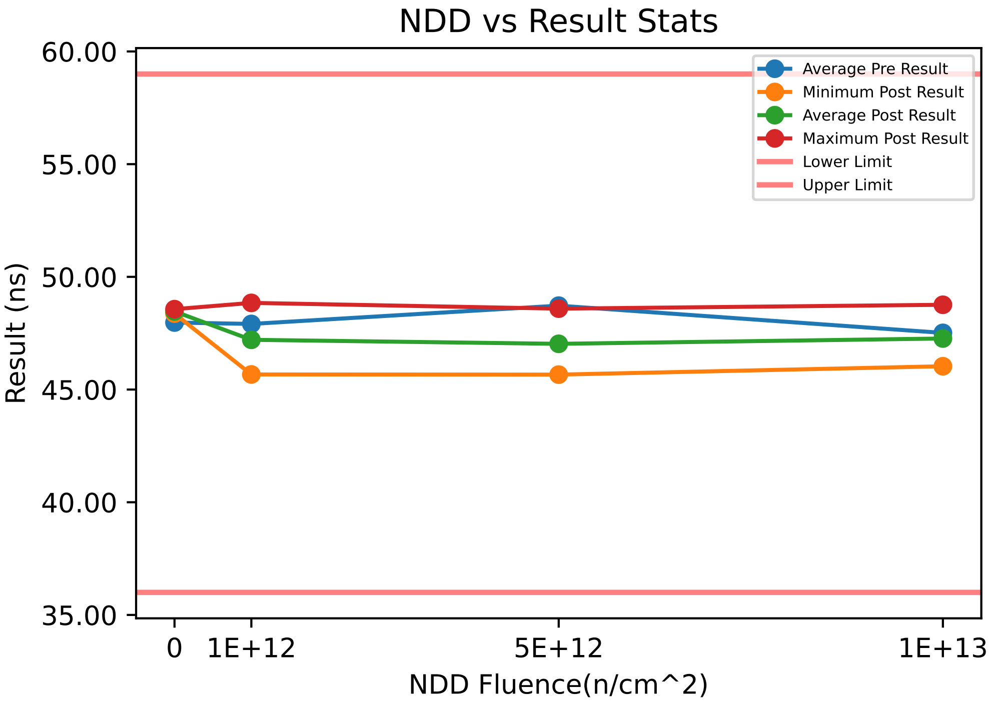
Test Results (Lower Limit = 0.0, Upper Limit = 10.0 (ns))

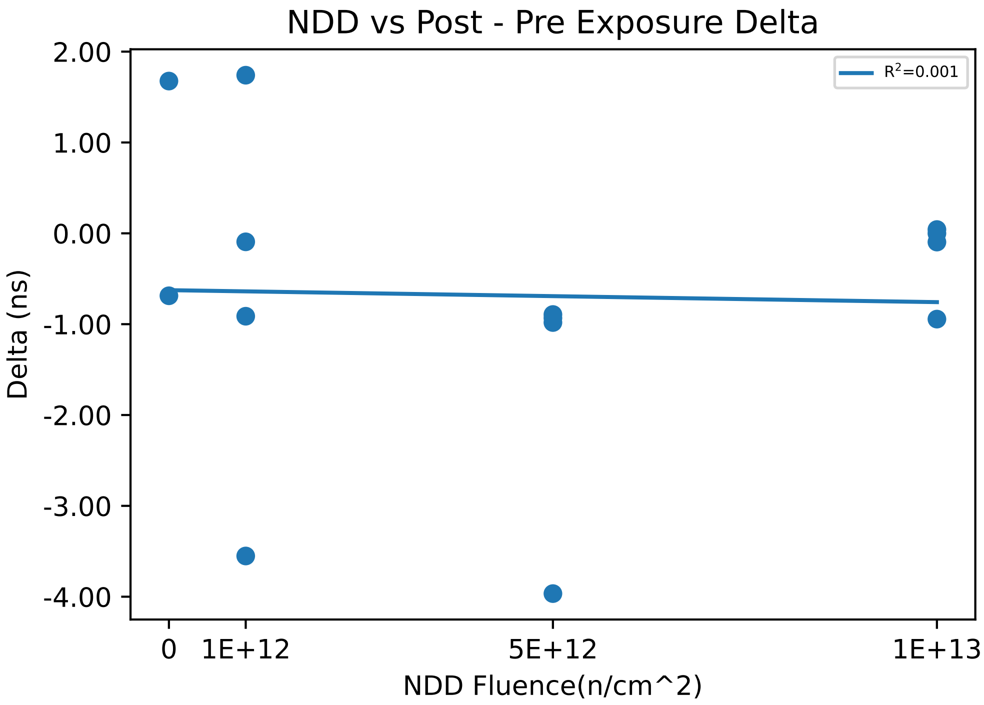
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	5.6485	4.1975	-1.451
2	0	Correlation	6.0238	3.9808	-2.043
30	1e+12	NDD unbiased	5.8137	3.8776	-1.9361
31	1e+12	NDD unbiased	5.7187	4.0207	-1.698
32	1e+12	NDD unbiased	5.0749	3.5786	-1.4963
33	1e+12	NDD unbiased	4.3654	4.2079	-0.1575
44	5e+12	NDD unbiased	5.996	4.5211	-1.4749
45	5e+12	NDD unbiased	5.5772	4.4122	-1.165
46	5e+12	NDD unbiased	5.3724	3.8454	-1.527
47	5e+12	NDD unbiased	6.0541	4.315	-1.7391
50	1e+13	NDD unbiased	3.7866	3.8728	0.0862
51	1e+13	NDD unbiased	5.986	4.3955	-1.5905
52	1e+13	NDD unbiased	4.4366	4.3296	-0.107
53	1e+13	NDD unbiased	4.2082	4.1953	-0.0129

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.6485	5.8361	6.0238	0.26538	3.9808	4.0892	4.1975	0.15323	-2.043	-1.747	-1.451	0.41861
1e+12	4.3654	5.2432	5.8137	0.67093	3.5786	3.9212	4.2079	0.26544	-1.9361	-1.322	-0.1575	0.79686
5e+12	5.3724	5.7499	6.0541	0.32936	3.8454	4.2734	4.5211	0.29751	-1.7391	-1.4765	-1.165	0.23703
1e+13	3.7866	4.6044	5.986	0.95964	3.8728	4.1983	4.3955	0.23244	-1.5905	-0.40605	0.0862	0.79356

Device Test: 96.3 T_RLH_LARGE(_DLH Dead Time Large 500kHz VIN_12V)





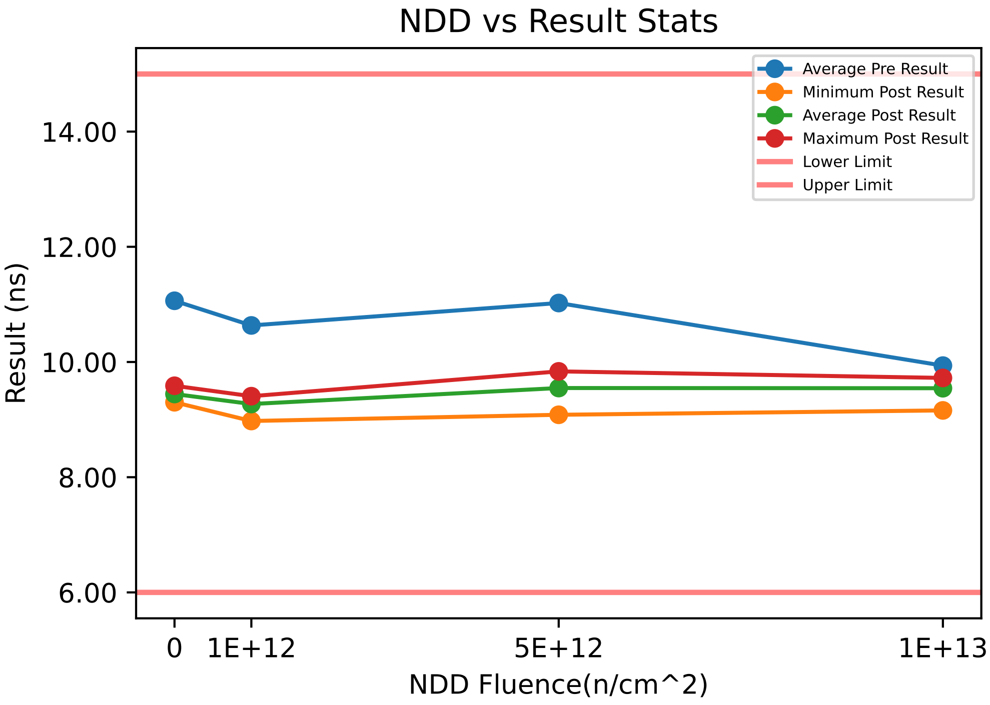
Test Results (Lower Limit = 36.0, Upper Limit = 59.0 (ns))

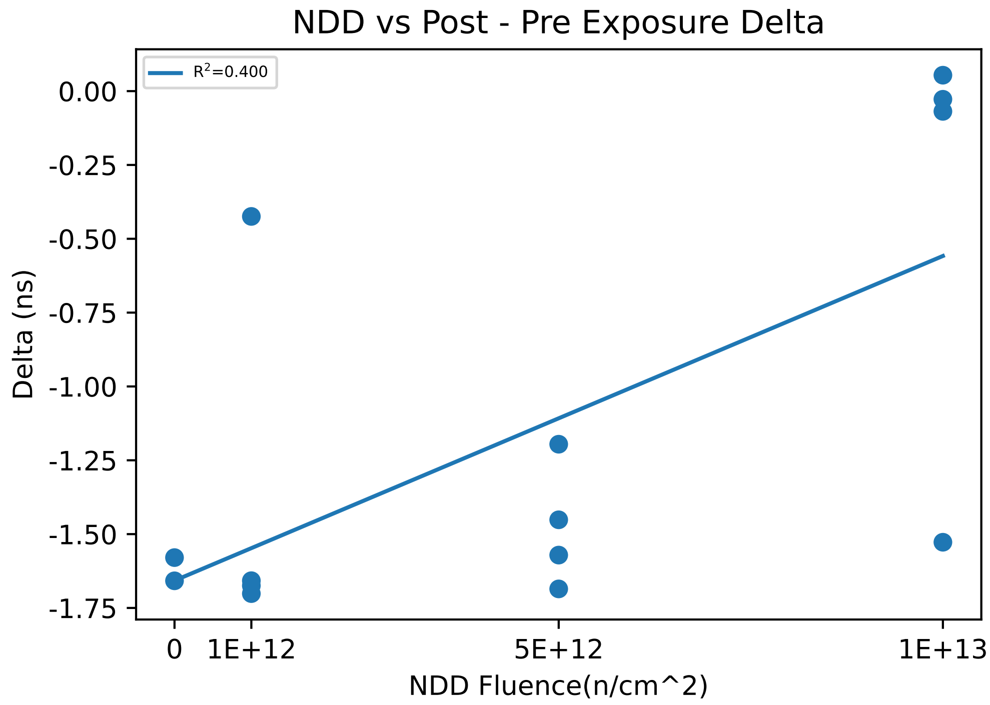
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	46.693	48.369	1.676
2	0	Correlation	49.254	48.566	-0.6874
30	1e+12	NDD unbiased	46.749	48.489	1.7406
31	1e+12	NDD unbiased	49.375	45.824	-3.5518
32	1e+12	NDD unbiased	46.582	45.669	-0.9126
33	1e+12	NDD unbiased	48.938	48.845	-0.0936
44	5e+12	NDD unbiased	49.086	48.192	-0.8936
45	5e+12	NDD unbiased	49.637	45.671	-3.9658
46	5e+12	NDD unbiased	49.522	48.589	-0.9329
47	5e+12	NDD unbiased	46.644	45.662	-0.9819
50	1e+13	NDD unbiased	47.886	47.885	-0.0007
51	1e+13	NDD unbiased	47.322	46.378	-0.9443
52	1e+13	NDD unbiased	46.13	46.033	-0.0962
53	1e+13	NDD unbiased	48.719	48.761	0.0417

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	46.693	47.973	49.254	1.8108	48.369	48.468	48.566	0.13958	-0.6874	0.4943	1.676	1.6712
1e+12	46.582	47.911	49.375	1.451	45.669	47.207	48.845	1.6935	-3.5518	-0.70435	1.7406	2.1986
5e+12	46.644	48.722	49.637	1.4057	45.662	47.029	48.589	1.5809	-3.9658	-1.6935	-0.8936	1.5153
1e+13	46.13	47.514	48.719	1.0868	46.033	47.264	48.761	1.2812	-0.9443	-0.24988	0.0417	0.46653

Device Test: 96.30 T_RHL_SMALL(_DHL Dead Time Small 2MHz VIN_12V)





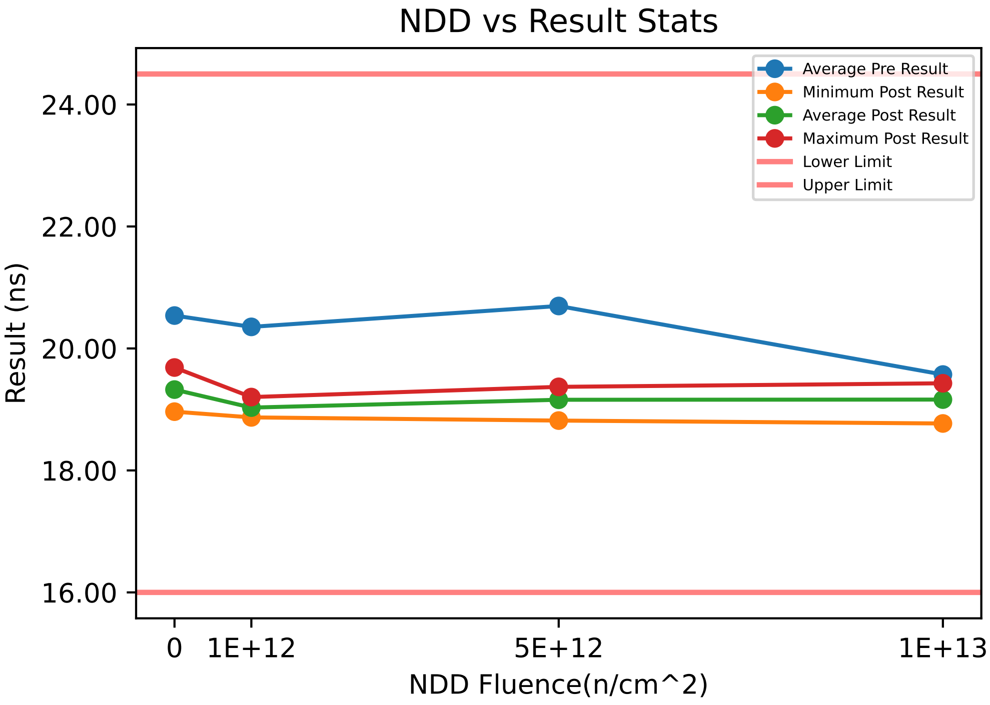
Test Results (Lower Limit = 6.0, Upper Limit = 15.0 (ns))

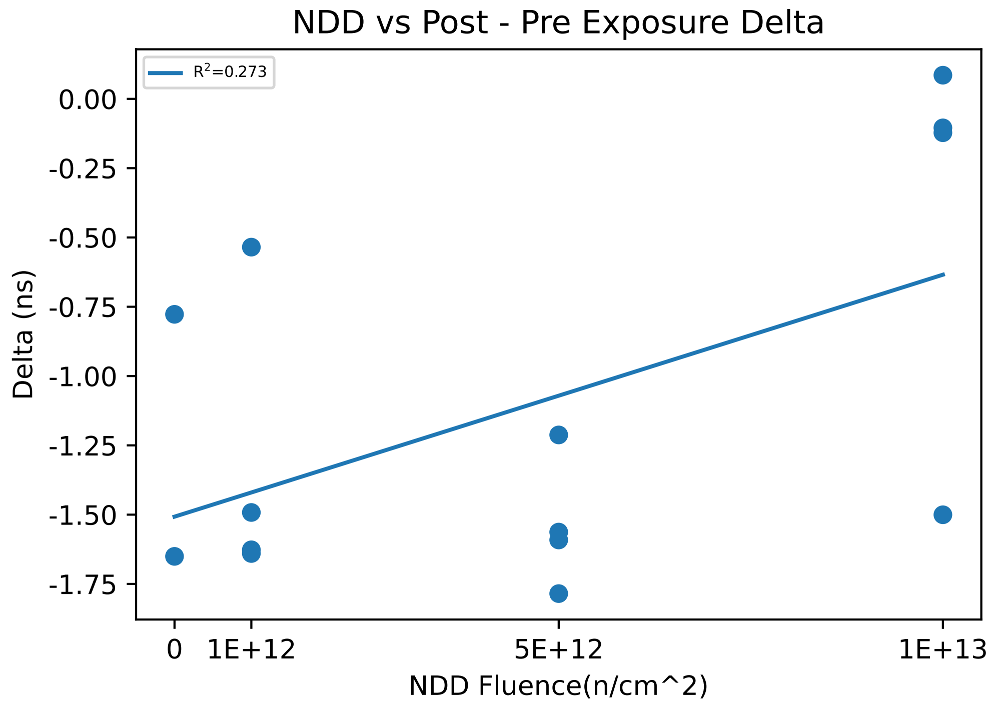
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	10.88	9.3009	-1.5795
2	0	Correlation	11.245	9.5874	-1.6581
30	1e+12	NDD unbiased	11.036	9.3611	-1.6746
31	1e+12	NDD unbiased	10.996	9.3383	-1.6577
32	1e+12	NDD unbiased	10.677	8.9757	-1.7014
33	1e+12	NDD unbiased	9.8306	9.4063	-0.4243
44	5e+12	NDD unbiased	11.289	9.8373	-1.4515
45	5e+12	NDD unbiased	10.838	9.6429	-1.1956
46	5e+12	NDD unbiased	10.769	9.0836	-1.6855
47	5e+12	NDD unbiased	11.2	9.6286	-1.571
50	1e+13	NDD unbiased	9.187	9.1594	-0.0276
51	1e+13	NDD unbiased	11.251	9.7236	-1.5275
52	1e+13	NDD unbiased	9.7741	9.7055	-0.0686
53	1e+13	NDD unbiased	9.5367	9.5906	0.0539

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	10.88	11.063	11.245	0.25816	9.3009	9.4442	9.5874	0.20259	-1.6581	-1.6188	-1.5795	0.055579
1e+12	9.8306	10.635	11.036	0.55968	8.9757	9.2704	9.4063	0.19846	-1.7014	-1.3645	-0.4243	0.62706
5e+12	10.769	11.024	11.289	0.25842	9.0836	9.5481	9.8373	0.32397	-1.6855	-1.4759	-1.1956	0.20987
1e+13	9.187	9.9372	11.251	0.9085	9.1594	9.5448	9.7236	0.26358	-1.5275	-0.39245	0.0539	0.75841

Device Test: 96.31 T_RHL_MID(_DHL Dead Time Mid 2MHz VIN_12V)


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

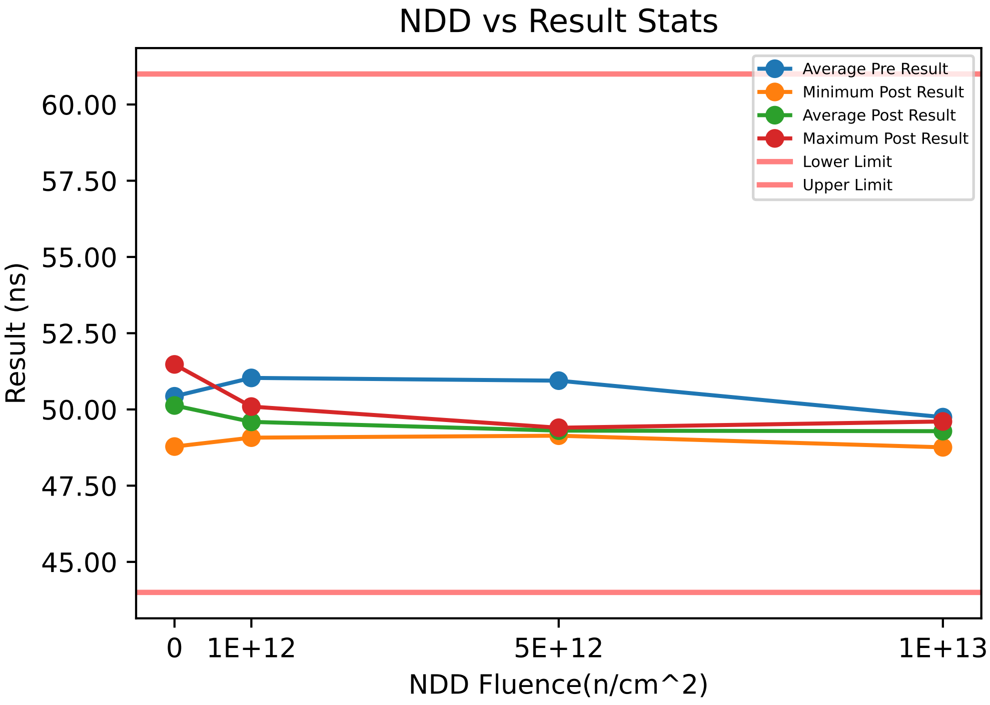
Test Results (Lower Limit = 16.0, Upper Limit = 24.5 (ns))

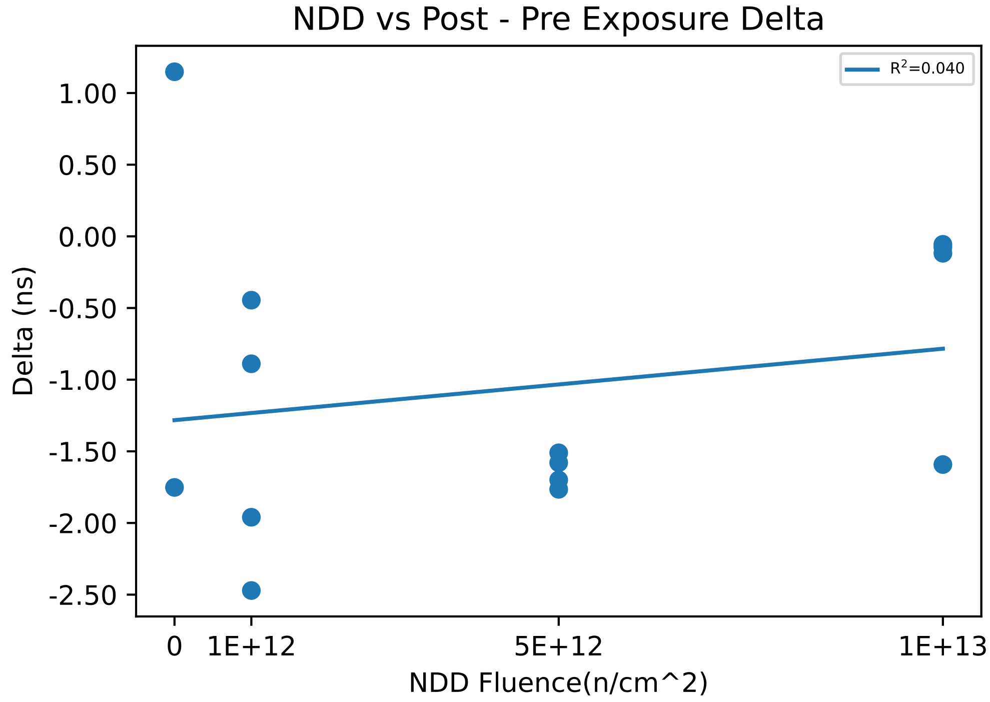
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	20.614	18.963	-1.6505
2	0	Correlation	20.465	19.687	-0.7773
30	1e+12	NDD unbiased	20.695	19.203	-1.4921
31	1e+12	NDD unbiased	20.667	19.04	-1.6268
32	1e+12	NDD unbiased	20.51	18.869	-1.6401
33	1e+12	NDD unbiased	19.544	19.009	-0.5349
44	5e+12	NDD unbiased	20.933	19.37	-1.5629
45	5e+12	NDD unbiased	20.486	19.274	-1.2124
46	5e+12	NDD unbiased	20.602	18.817	-1.7848
47	5e+12	NDD unbiased	20.764	19.172	-1.5913
50	1e+13	NDD unbiased	18.684	18.77	0.0854
51	1e+13	NDD unbiased	20.929	19.429	-1.5004
52	1e+13	NDD unbiased	19.448	19.344	-0.1046
53	1e+13	NDD unbiased	19.226	19.104	-0.1222

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	20.465	20.539	20.614	0.10564	18.963	19.325	19.687	0.5118	-1.6505	-1.2139	-0.7773	0.61745
1e+12	19.544	20.354	20.695	0.54615	18.869	19.03	19.203	0.13679	-1.6401	-1.3235	-0.5349	0.52995
5e+12	20.486	20.696	20.933	0.19457	18.817	19.158	19.37	0.24139	-1.7848	-1.5378	-1.2124	0.23832
1e+13	18.684	19.572	20.929	0.95988	18.77	19.162	19.429	0.29509	-1.5004	-0.41045	0.0854	0.73269

Device Test: 96.32 T_RHL_LARGE(_DHL Dead Time Large 2MHz VIN_12V)





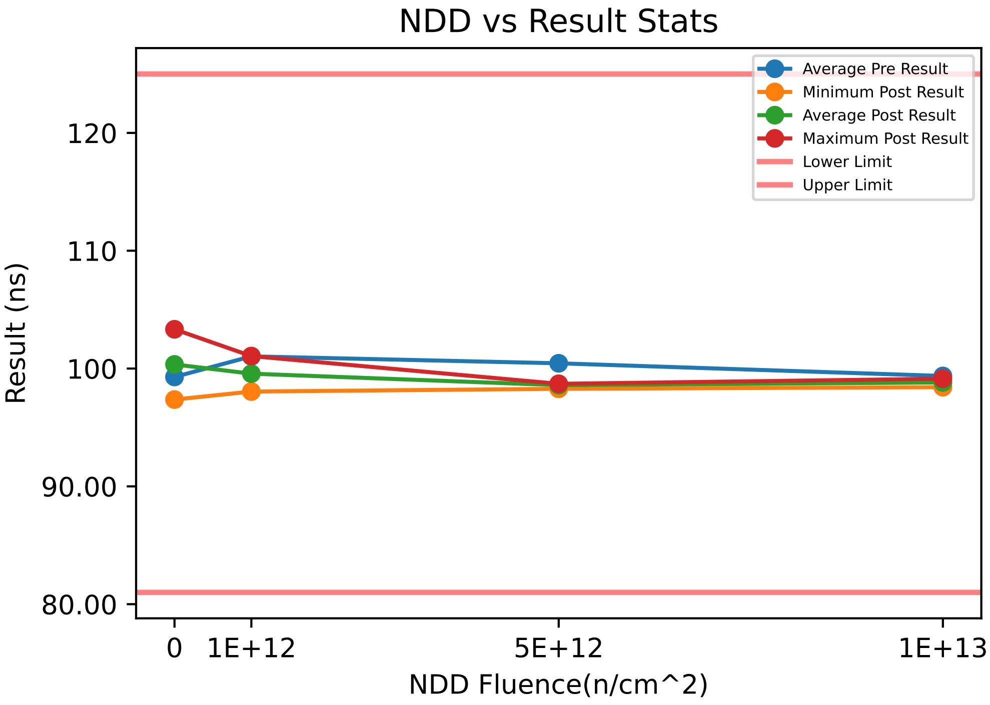
Test Results (Lower Limit = 44.0, Upper Limit = 61.0 (ns))

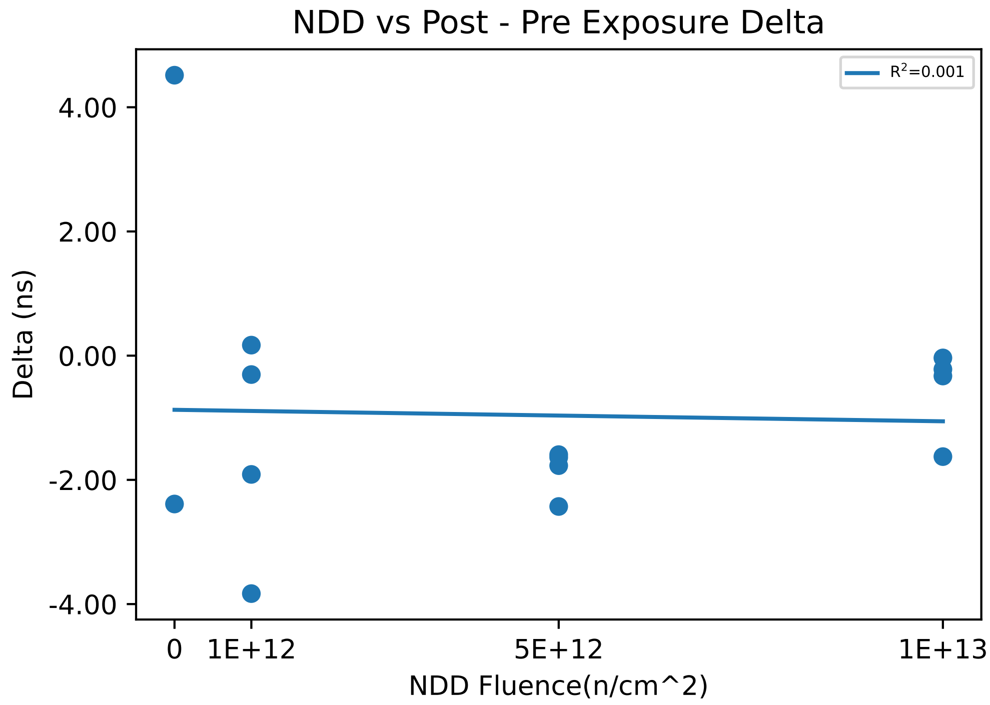
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	50.535	48.783	-1.7519
2	0	Correlation	50.328	51.477	1.1485
30	1e+12	NDD unbiased	50.983	50.094	-0.8891
31	1e+12	NDD unbiased	51.816	49.345	-2.4712
32	1e+12	NDD unbiased	51.816	49.856	-1.96
33	1e+12	NDD unbiased	49.52	49.075	-0.4453
44	5e+12	NDD unbiased	50.91	49.4	-1.5104
45	5e+12	NDD unbiased	50.964	49.384	-1.5794
46	5e+12	NDD unbiased	50.904	49.139	-1.765
47	5e+12	NDD unbiased	50.996	49.297	-1.6995
50	1e+13	NDD unbiased	48.875	48.757	-0.1181
51	1e+13	NDD unbiased	51.197	49.605	-1.5922
52	1e+13	NDD unbiased	49.571	49.515	-0.0556
53	1e+13	NDD unbiased	49.347	49.271	-0.0761

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	50.328	50.431	50.535	0.14595	48.783	50.13	51.477	1.9049	-1.7519	-0.3017	1.1485	2.0509
1e+12	49.52	51.034	51.816	1.083	49.075	49.592	50.094	0.46561	-2.4712	-1.4414	-0.4453	0.93571
5e+12	50.904	50.943	50.996	0.044465	49.139	49.305	49.4	0.11971	-1.765	-1.6386	-1.5104	0.11493
1e+13	48.875	49.748	51.197	1.009	48.757	49.287	49.605	0.38041	-1.5922	-0.4605	-0.0556	0.75492

Device Test: 96.33 T_RHL_MAX(_DHL Dead Time Max 2MHz VIN_12V)


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

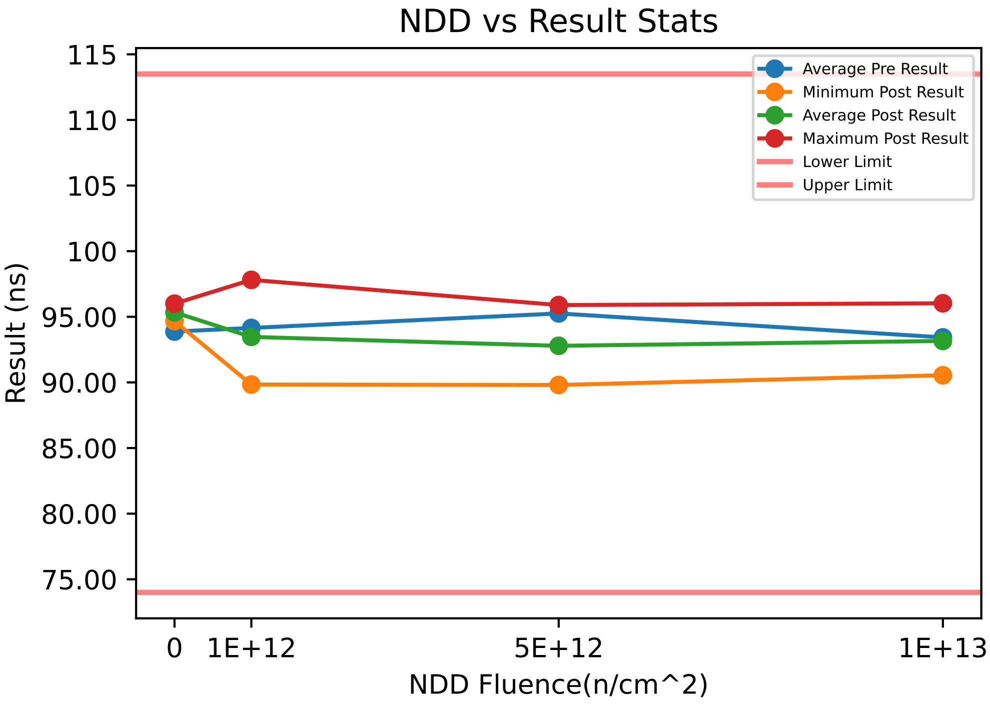
Test Results (Lower Limit = 81.0, Upper Limit = 125.0 (ns))

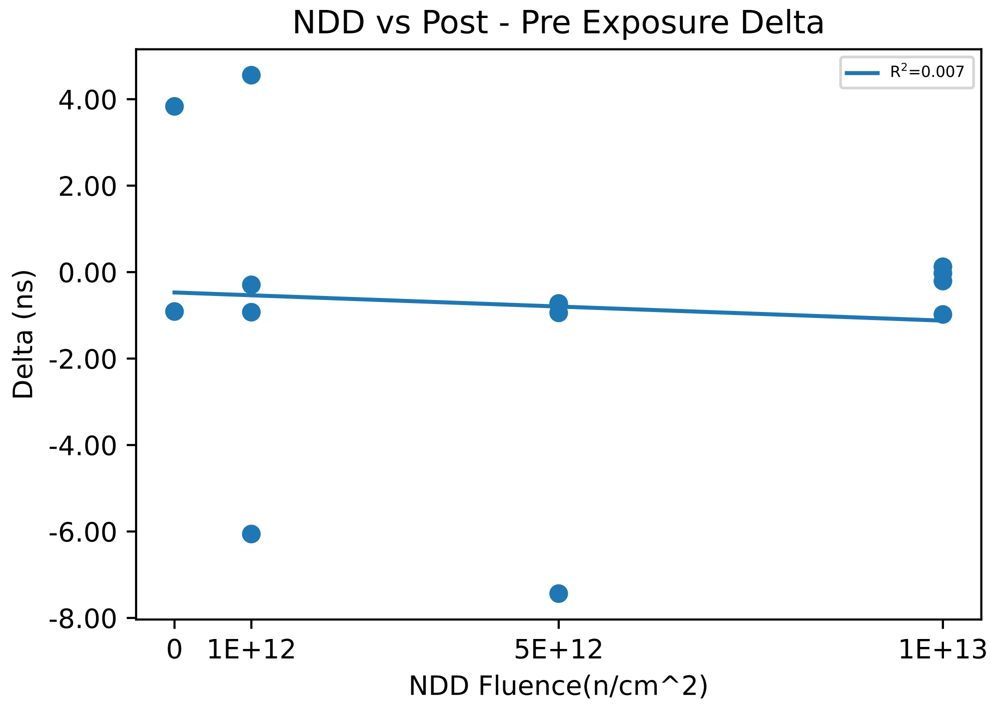
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	99.754	97.366	-2.3886
2	0	Correlation	98.816	103.33	4.516
30	1e+12	NDD unbiased	100.29	100.46	0.1696
31	1e+12	NDD unbiased	102.53	98.697	-3.8312
32	1e+12	NDD unbiased	102.97	101.06	-1.9121
33	1e+12	NDD unbiased	98.351	98.047	-0.3042
44	5e+12	NDD unbiased	99.918	98.279	-1.6381
45	5e+12	NDD unbiased	101.1	98.675	-2.4286
46	5e+12	NDD unbiased	100.28	98.69	-1.5935
47	5e+12	NDD unbiased	100.47	98.704	-1.7706
50	1e+13	NDD unbiased	98.745	98.417	-0.3277
51	1e+13	NDD unbiased	100.61	98.986	-1.6255
52	1e+13	NDD unbiased	98.954	98.735	-0.2198
53	1e+13	NDD unbiased	99.171	99.135	-0.0363

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	98.816	99.285	99.754	0.66348	97.366	100.35	103.33	4.2188	-2.3886	1.0637	4.516	4.8823
1e+12	98.351	101.03	102.97	2.1397	98.047	99.565	101.06	1.4249	-3.8312	-1.4695	0.1696	1.8091
5e+12	99.918	100.44	101.1	0.49621	98.279	98.587	98.704	0.2055	-2.4286	-1.8577	-1.5935	0.38796
1e+13	98.745	99.371	100.61	0.84566	98.417	98.818	99.135	0.31421	-1.6255	-0.55233	-0.0363	0.72549

Device Test: 96.4 T_RLH_MAX(_DLH Dead Time Max 500kHz VIN_12V)





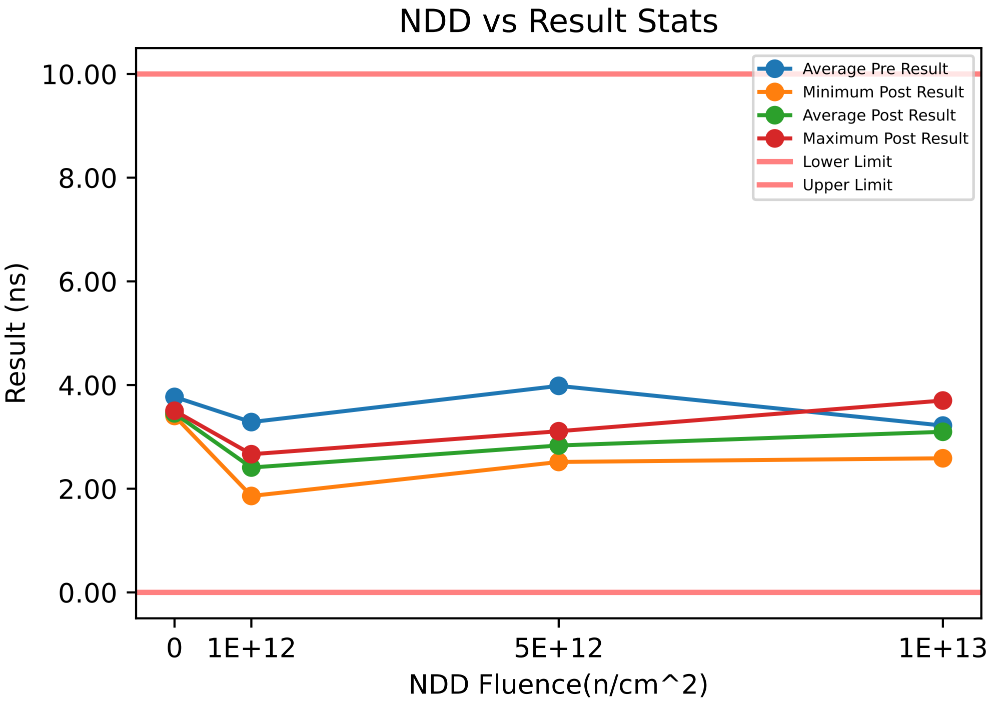
Test Results (Lower Limit = 74.0, Upper Limit = 113.5 (ns))

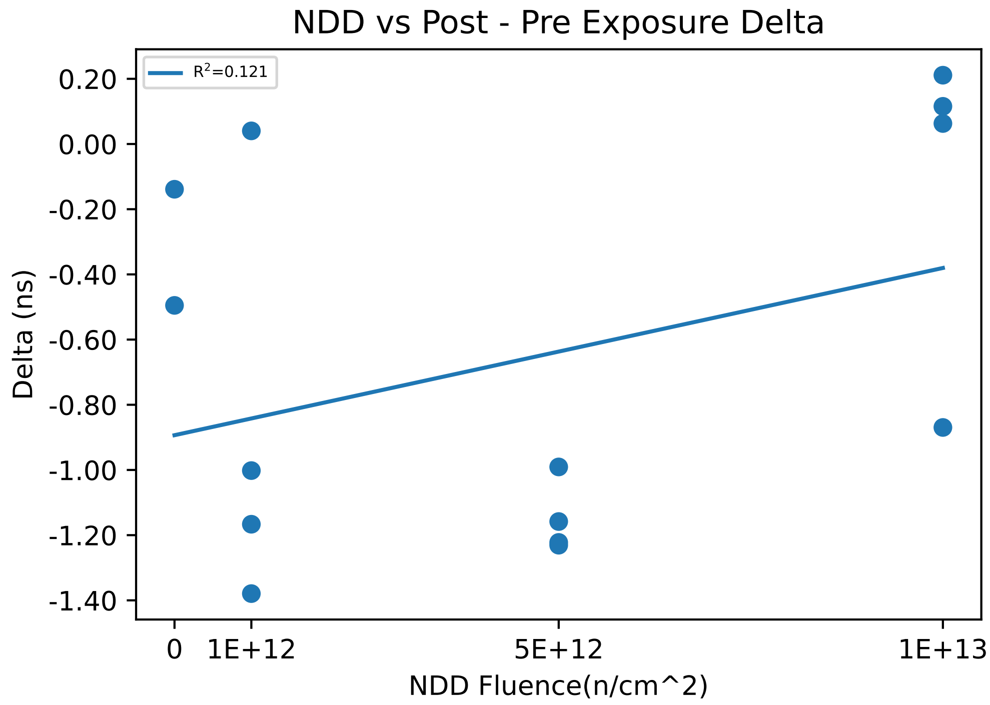
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	90.839	94.672	3.8334
2	0	Correlation	96.913	96.002	-0.9114
30	1e+12	NDD unbiased	91.281	95.836	4.5551
31	1e+12	NDD unbiased	96.44	90.382	-6.058
32	1e+12	NDD unbiased	90.767	89.84	-0.9272
33	1e+12	NDD unbiased	98.11	97.816	-0.2949
44	5e+12	NDD unbiased	96.415	95.653	-0.7616
45	5e+12	NDD unbiased	97.241	89.805	-7.4366
46	5e+12	NDD unbiased	96.619	95.894	-0.7253
47	5e+12	NDD unbiased	90.75	89.807	-0.9426
50	1e+13	NDD unbiased	94.999	94.792	-0.2071
51	1e+13	NDD unbiased	91.525	90.546	-0.9792
52	1e+13	NDD unbiased	91.295	91.268	-0.0264
53	1e+13	NDD unbiased	95.905	96.029	0.1241

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	90.839	93.876	96.913	4.2956	94.672	95.337	96.002	0.94052	-0.9114	1.461	3.8334	3.3551
1e+12	90.767	94.15	98.11	3.679	89.84	93.468	97.816	3.9663	-6.058	-0.68125	4.5551	4.3412
5e+12	90.75	95.256	97.241	3.0248	89.805	92.79	95.894	3.4468	-7.4366	-2.4665	-0.7253	3.3147
1e+13	91.295	93.431	95.905	2.3647	90.546	93.159	96.029	2.665	-0.9792	-0.27215	0.1241	0.49043

Device Test: 96.5 T_RLH_MIN(_DLH Dead Time Min 1MHz VIN_12V)


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

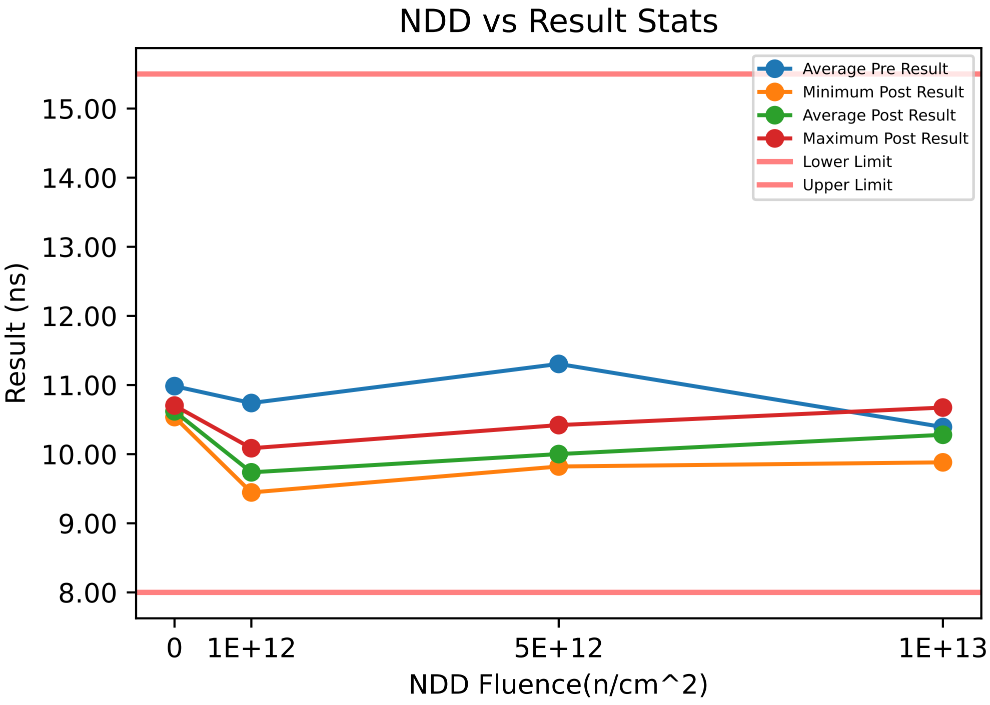
Test Results (Lower Limit = 0.0, Upper Limit = 10.0 (ns))

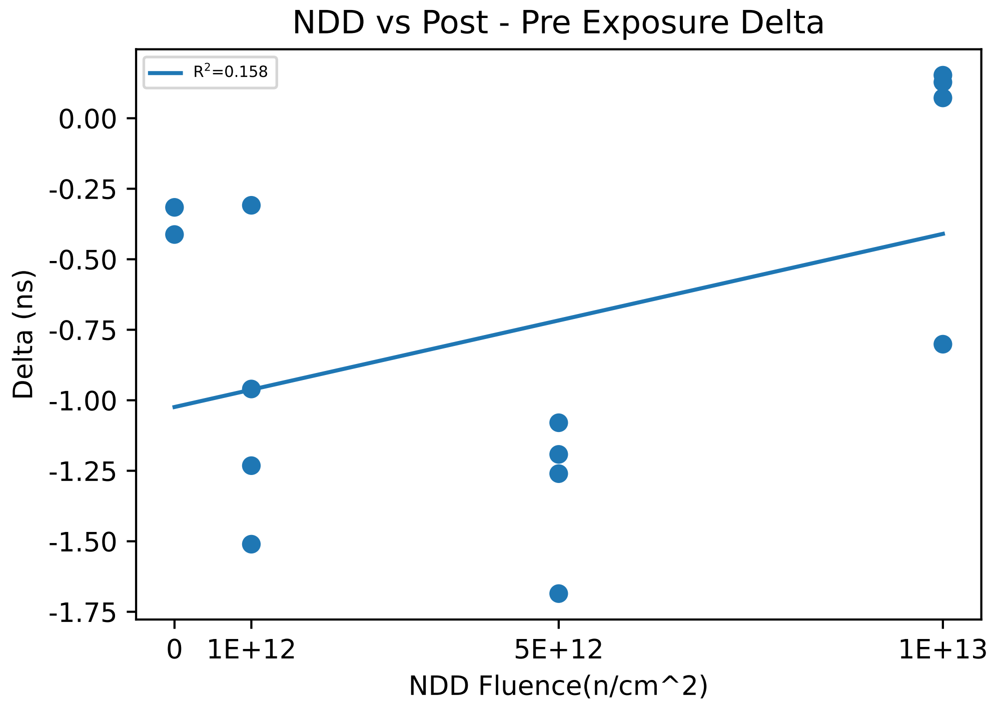
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	3.8988	3.4037	-0.4951
2	0	Correlation	3.6431	3.5043	-0.1388
30	1e+12	NDD unbiased	3.8516	2.4723	-1.3793
31	1e+12	NDD unbiased	3.832	2.6655	-1.1665
32	1e+12	NDD unbiased	3.6386	2.6367	-1.0019
33	1e+12	NDD unbiased	1.8199	1.8602	0.0403
44	5e+12	NDD unbiased	3.7385	2.5162	-1.2223
45	5e+12	NDD unbiased	4.0196	2.8614	-1.1582
46	5e+12	NDD unbiased	4.0998	3.1091	-0.9907
47	5e+12	NDD unbiased	4.0789	2.8481	-1.2308
50	1e+13	NDD unbiased	2.3761	2.5872	0.2111
51	1e+13	NDD unbiased	4.5709	3.7013	-0.8696
52	1e+13	NDD unbiased	2.7715	2.8871	0.1156
53	1e+13	NDD unbiased	3.1543	3.2172	0.0629

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.6431	3.771	3.8988	0.18081	3.4037	3.454	3.5043	0.071135	-0.4951	-0.31695	-0.1388	0.25194
1e+12	1.8199	3.2855	3.8516	0.9818	1.8602	2.4087	2.6655	0.37542	-1.3793	-0.87685	0.0403	0.63065
5e+12	3.7385	3.9842	4.0998	0.16729	2.5162	2.8337	3.1091	0.24333	-1.2308	-1.1505	-0.9907	0.11135
1e+13	2.3761	3.2182	4.5709	0.95613	2.5872	3.0982	3.7013	0.47735	-0.8696	-0.12	0.2111	0.50348

Device Test: 96.6 T_RLH_SMALL(_DLH Dead Time Small 1MHz VIN_12V)


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

Test Results (Lower Limit = 8.0, Upper Limit = 15.5 (ns))

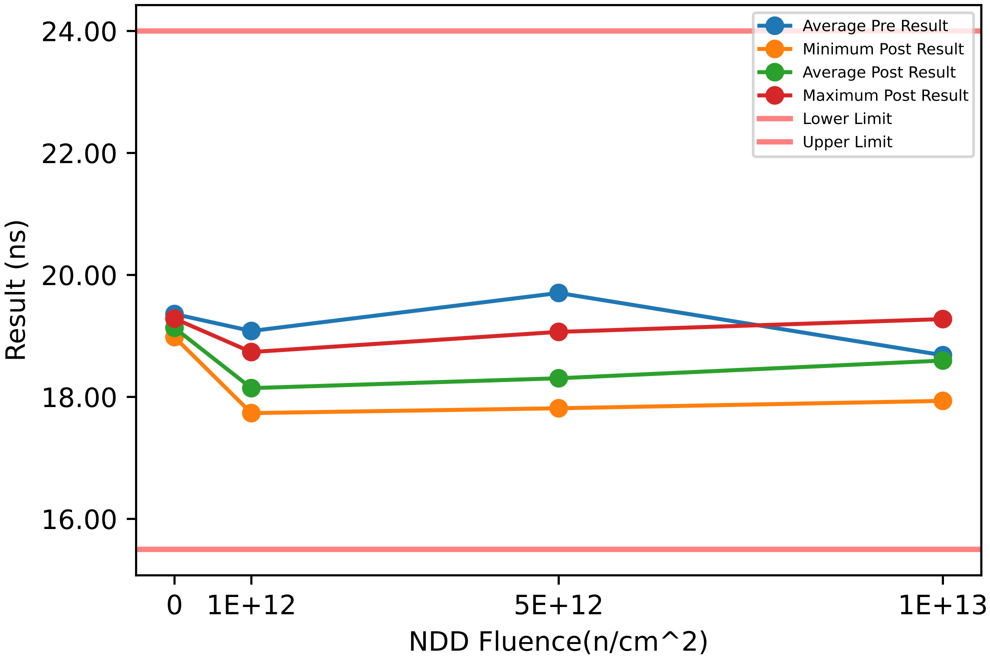
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	10.853	10.537	-0.316
2	0	Correlation	11.116	10.703	-0.4123
30	1e+12	NDD unbiased	11.046	10.086	-0.96
31	1e+12	NDD unbiased	11.214	9.704	-1.5103
32	1e+12	NDD unbiased	10.944	9.7125	-1.2319
33	1e+12	NDD unbiased	9.7549	9.4462	-0.3087
44	5e+12	NDD unbiased	11.019	9.939	-1.0797
45	5e+12	NDD unbiased	11.509	9.8236	-1.6855
46	5e+12	NDD unbiased	11.612	10.42	-1.1919
47	5e+12	NDD unbiased	11.082	9.8216	-1.2602
50	1e+13	NDD unbiased	9.868	9.9401	0.0721
51	1e+13	NDD unbiased	11.427	10.625	-0.8012
52	1e+13	NDD unbiased	9.7289	9.8815	0.1526
53	1e+13	NDD unbiased	10.547	10.674	0.1277

Test Statistics (ns)

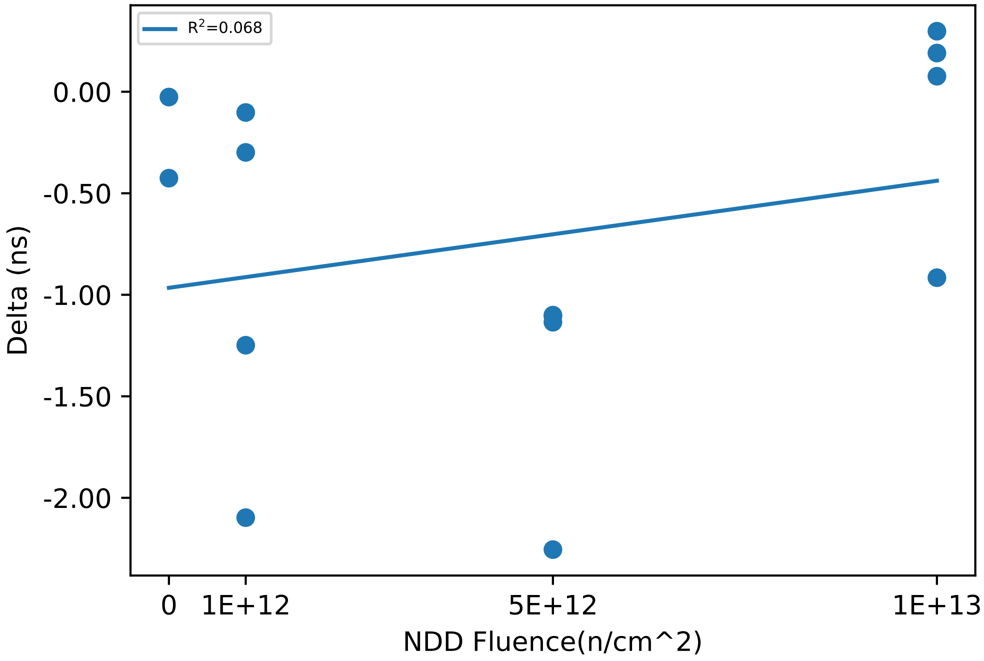
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	10.853	10.984	11.116	0.18597	10.537	10.62	10.703	0.11787	-0.4123	-0.36415	-0.316	0.068094
1e+12	9.7549	10.74	11.214	0.66602	9.4462	9.7371	10.086	0.2633	-1.5103	-1.0027	-0.3087	0.51434
5e+12	11.019	11.305	11.612	0.29882	9.8216	10.001	10.42	0.28484	-1.6855	-1.3043	-1.0797	0.26479
1e+13	9.7289	10.393	11.427	0.77645	9.8815	10.28	10.674	0.42786	-0.8012	-0.1122	0.1526	0.46056

Device Test: 96.7 T_RLH_MID(_DLH Dead Time Mid 1MHz VIN_12V)

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



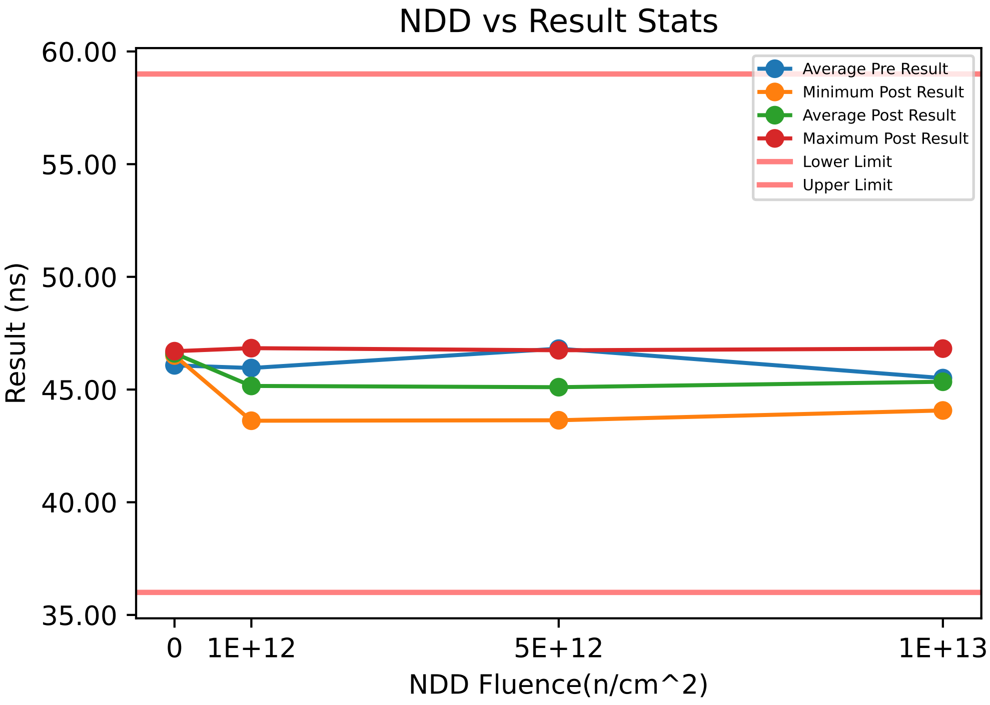
Test Results (Lower Limit = 15.5, Upper Limit = 24.0 (ns))

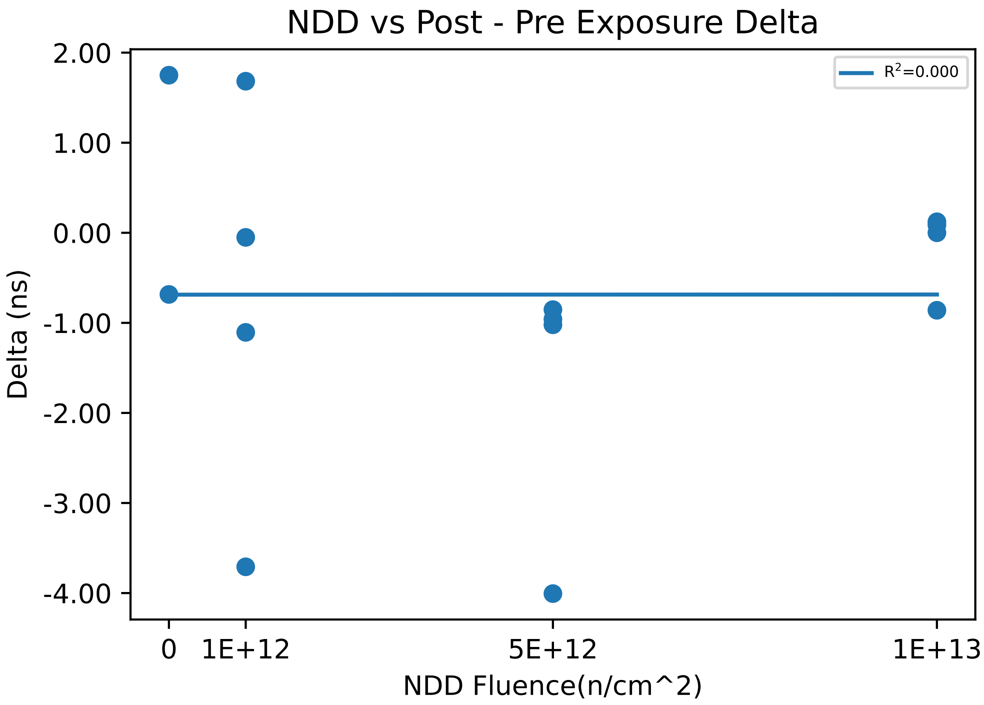
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	19.007	18.981	-0.0262
2	0	Correlation	19.71	19.285	-0.4256
30	1e+12	NDD unbiased	19.035	18.736	-0.2988
31	1e+12	NDD unbiased	19.832	17.735	-2.0976
32	1e+12	NDD unbiased	19.032	17.784	-1.2485
33	1e+12	NDD unbiased	18.425	18.323	-0.1022
44	5e+12	NDD unbiased	19.597	18.492	-1.1047
45	5e+12	NDD unbiased	20.069	17.814	-2.255
46	5e+12	NDD unbiased	20.167	19.066	-1.1002
47	5e+12	NDD unbiased	18.987	17.852	-1.1352
50	1e+13	NDD unbiased	18.335	18.525	0.1906
51	1e+13	NDD unbiased	19.565	18.649	-0.9159
52	1e+13	NDD unbiased	17.859	17.935	0.0764
53	1e+13	NDD unbiased	18.978	19.276	0.2982

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	19.007	19.359	19.71	0.49695	18.981	19.133	19.285	0.21454	-0.4256	-0.2259	-0.0262	0.28242
1e+12	18.425	19.081	19.832	0.57717	17.735	18.144	18.736	0.47597	-2.0976	-0.93677	-0.1022	0.92163
5e+12	18.987	19.705	20.167	0.53947	17.814	18.306	19.066	0.59481	-2.255	-1.3988	-1.1002	0.57103
1e+13	17.859	18.684	19.565	0.74515	17.935	18.597	19.276	0.54982	-0.9159	-0.087675	0.2982	0.55953

Device Test: 96.8 T_RLH_LARGE(_DLH Dead Time Large 1MHz VIN_12V)


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

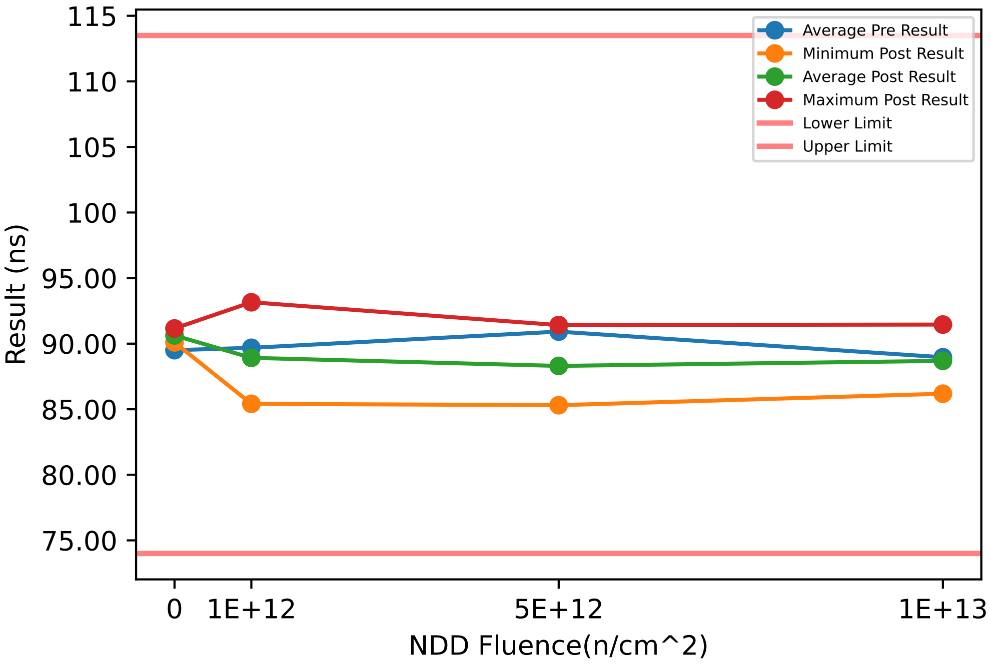
Test Results (Lower Limit = 36.0, Upper Limit = 59.0 (ns))

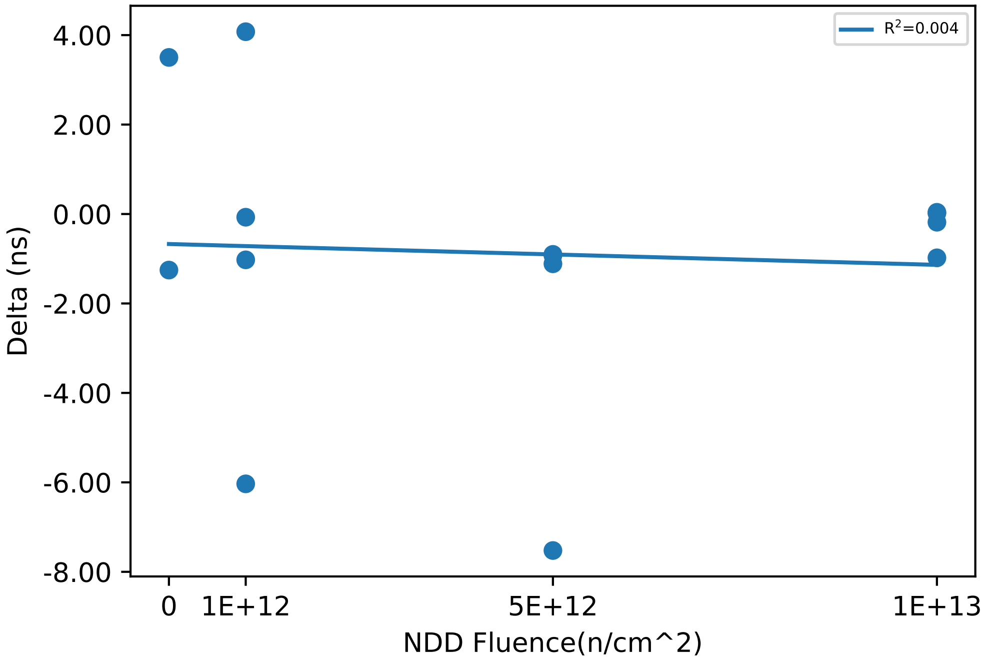
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	44.761	46.51	1.7497
2	0	Correlation	47.386	46.702	-0.6844
30	1e+12	NDD unbiased	44.774	46.457	1.6829
31	1e+12	NDD unbiased	47.438	43.73	-3.7085
32	1e+12	NDD unbiased	44.722	43.616	-1.1057
33	1e+12	NDD unbiased	46.887	46.836	-0.0509
44	5e+12	NDD unbiased	47.202	46.349	-0.8531
45	5e+12	NDD unbiased	47.695	43.689	-4.0059
46	5e+12	NDD unbiased	47.702	46.742	-0.9599
47	5e+12	NDD unbiased	44.659	43.637	-1.0213
50	1e+13	NDD unbiased	45.987	46.074	0.0874
51	1e+13	NDD unbiased	45.281	44.421	-0.8602
52	1e+13	NDD unbiased	43.95	44.072	0.1223
53	1e+13	NDD unbiased	46.816	46.816	0.0003

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	44.761	46.073	47.386	1.8566	46.51	46.606	46.702	0.13541	-0.6844	0.53265	1.7497	1.7212
1e+12	44.722	45.955	47.438	1.4124	43.616	45.16	46.836	1.7244	-3.7085	-0.79555	1.6829	2.2567
5e+12	44.659	46.815	47.702	1.4563	43.637	45.105	46.742	1.672	-4.0059	-1.71	-0.8531	1.5321
1e+13	43.95	45.508	46.816	1.2137	44.072	45.346	46.816	1.3128	-0.8602	-0.16255	0.1223	0.46792

Device Test: 96.9 T_RLH_MAX(_DLH Dead Time Max 1MHz VIN_12V)


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

Test Results (Lower Limit = 74.0, Upper Limit = 113.5 (ns))

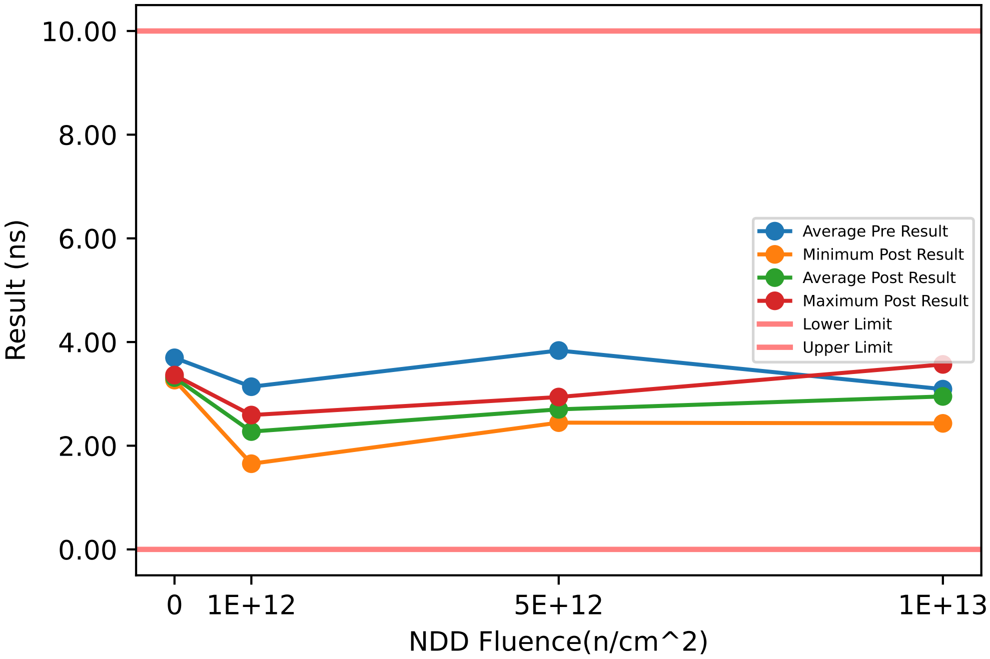
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	86.596	90.097	3.5012
2	0	Correlation	92.412	91.158	-1.2532
30	1e+12	NDD unbiased	87.087	91.163	4.0757
31	1e+12	NDD unbiased	91.975	85.942	-6.0329
32	1e+12	NDD unbiased	86.438	85.413	-1.0245
33	1e+12	NDD unbiased	93.228	93.157	-0.0716
44	5e+12	NDD unbiased	92.033	91.131	-0.9023
45	5e+12	NDD unbiased	92.88	85.356	-7.5236
46	5e+12	NDD unbiased	92.341	91.416	-0.9249
47	5e+12	NDD unbiased	86.42	85.307	-1.1129
50	1e+13	NDD unbiased	90.517	90.334	-0.1833
51	1e+13	NDD unbiased	87.162	86.183	-0.9796
52	1e+13	NDD unbiased	86.736	86.774	0.0382
53	1e+13	NDD unbiased	91.436	91.456	0.0199

Test Statistics (ns)

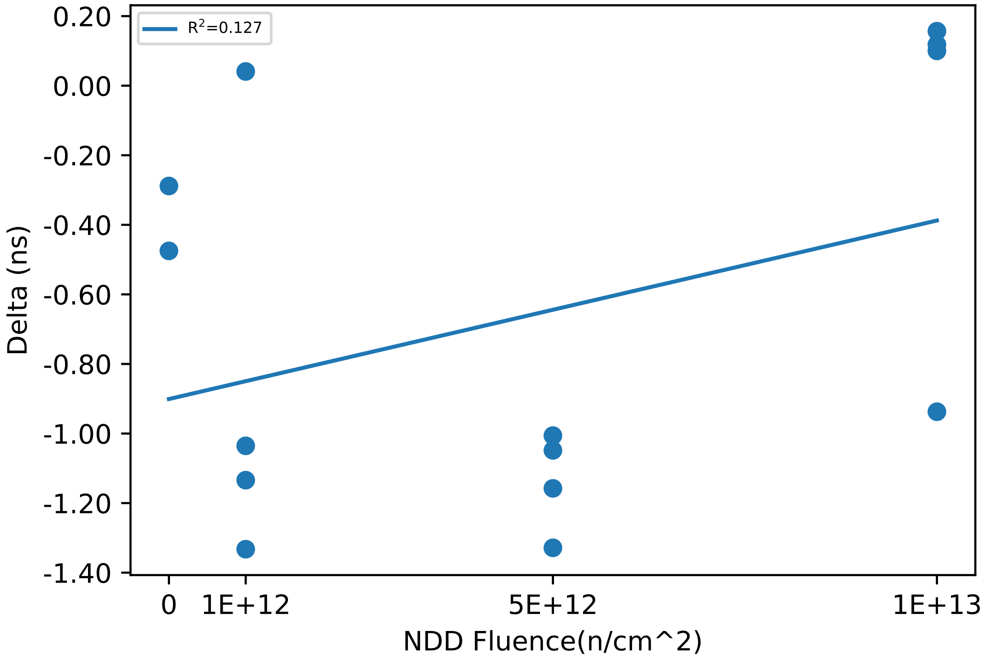
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	86.596	89.504	92.412	4.112	90.097	90.628	91.158	0.7501	-1.2532	1.124	3.5012	3.3619
1e+12	86.438	89.682	93.228	3.4203	85.413	88.919	93.157	3.836	-6.0329	-0.76332	4.0757	4.1526
5e+12	86.42	90.919	92.88	3.0193	85.307	88.303	91.416	3.4326	-7.5236	-2.6159	-0.9023	3.2731
1e+13	86.736	88.963	91.436	2.3617	86.183	88.687	91.456	2.6018	-0.9796	-0.2762	0.0382	0.47956

Device Test: 97.0 T_RLH_MIN(_DLH Dead Time Min 500kHz VIN_14V)

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



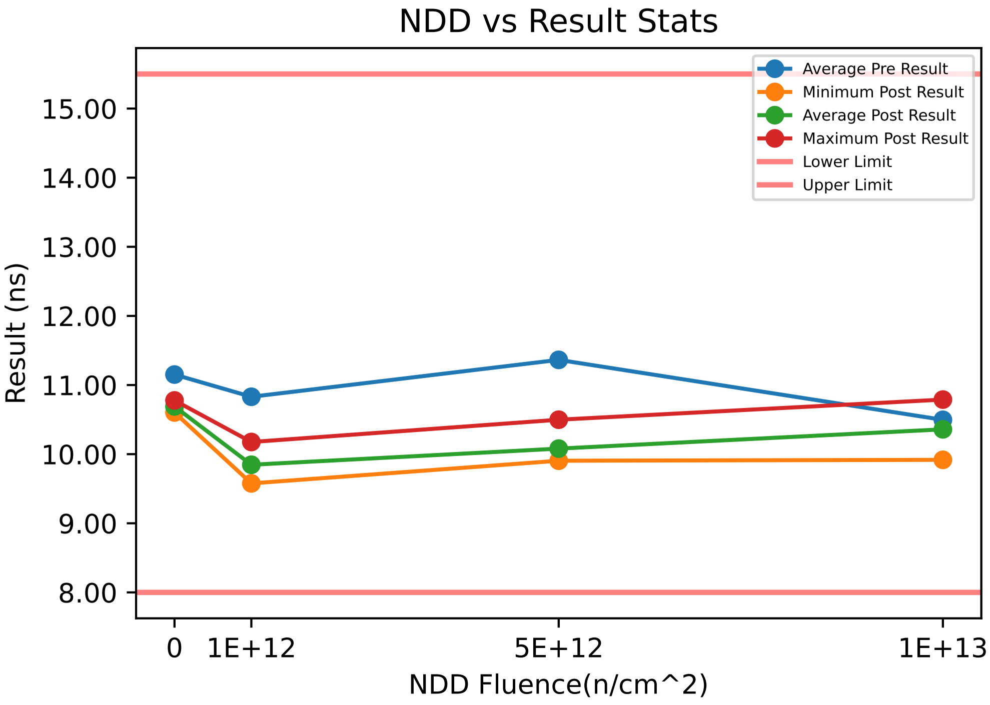
Test Results (Lower Limit = 0.0, Upper Limit = 10.0 (ns))

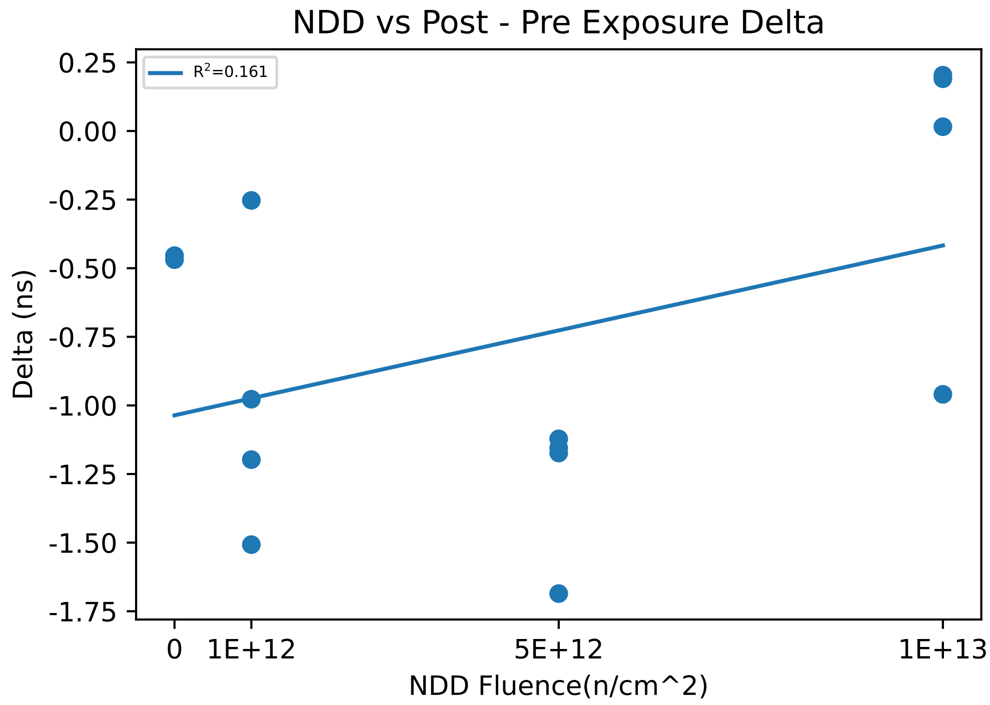
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	3.7403	3.2654	-0.4749
2	0	Correlation	3.6512	3.3628	-0.2884
30	1e+12	NDD unbiased	3.7264	2.3939	-1.3325
31	1e+12	NDD unbiased	3.6269	2.5916	-1.0353
32	1e+12	NDD unbiased	3.5874	2.4533	-1.1341
33	1e+12	NDD unbiased	1.6118	1.6526	0.0408
44	5e+12	NDD unbiased	3.4936	2.4452	-1.0484
45	5e+12	NDD unbiased	3.8895	2.7318	-1.1577
46	5e+12	NDD unbiased	3.9454	2.9394	-1.006
47	5e+12	NDD unbiased	4.0181	2.6895	-1.3286
50	1e+13	NDD unbiased	2.2743	2.431	0.1567
51	1e+13	NDD unbiased	4.5057	3.5684	-0.9373
52	1e+13	NDD unbiased	2.6037	2.7219	0.1182
53	1e+13	NDD unbiased	2.9811	3.0812	0.1001

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.6512	3.6957	3.7403	0.063003	3.2654	3.3141	3.3628	0.068872	-0.4749	-0.38165	-0.2884	0.13188
1e+12	1.6118	3.1381	3.7264	1.0192	1.6526	2.2729	2.5916	0.42171	-1.3325	-0.86528	0.0408	0.61656
5e+12	3.4936	3.8366	4.0181	0.23468	2.4452	2.7015	2.9394	0.20277	-1.3286	-1.1352	-1.006	0.14392
1e+13	2.2743	3.0912	4.5057	0.98622	2.431	2.9506	3.5684	0.49025	-0.9373	-0.14058	0.1567	0.53167

Device Test: 97.1 T_RLH_SMALL(_DLH Dead Time Small 500kHz VIN_14V)





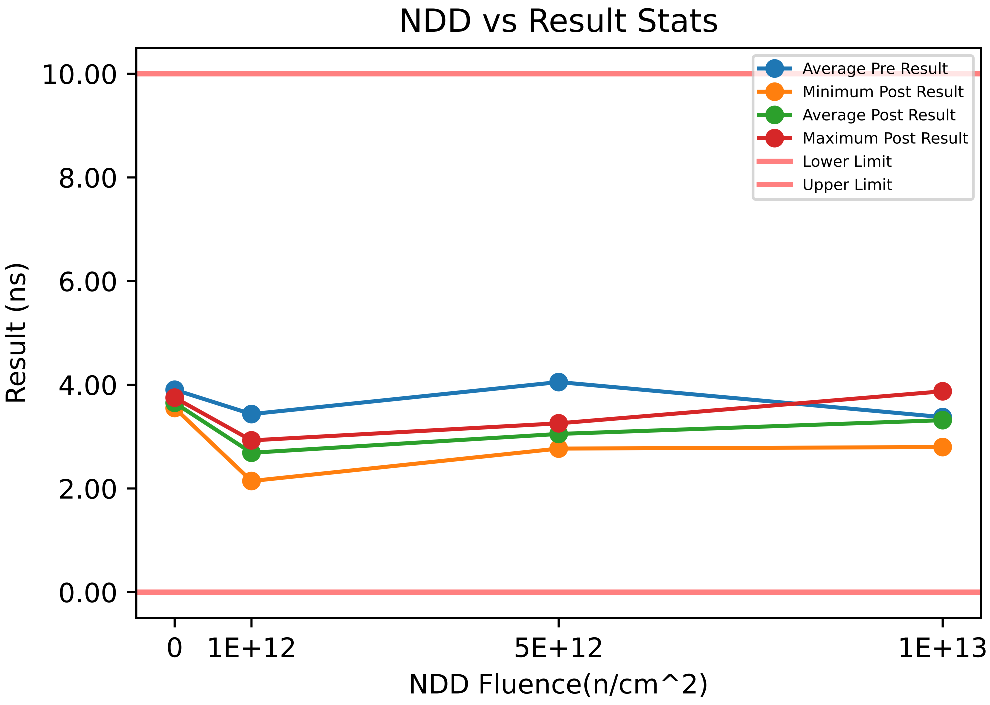
Test Results (Lower Limit = 8.0, Upper Limit = 15.5 (ns))

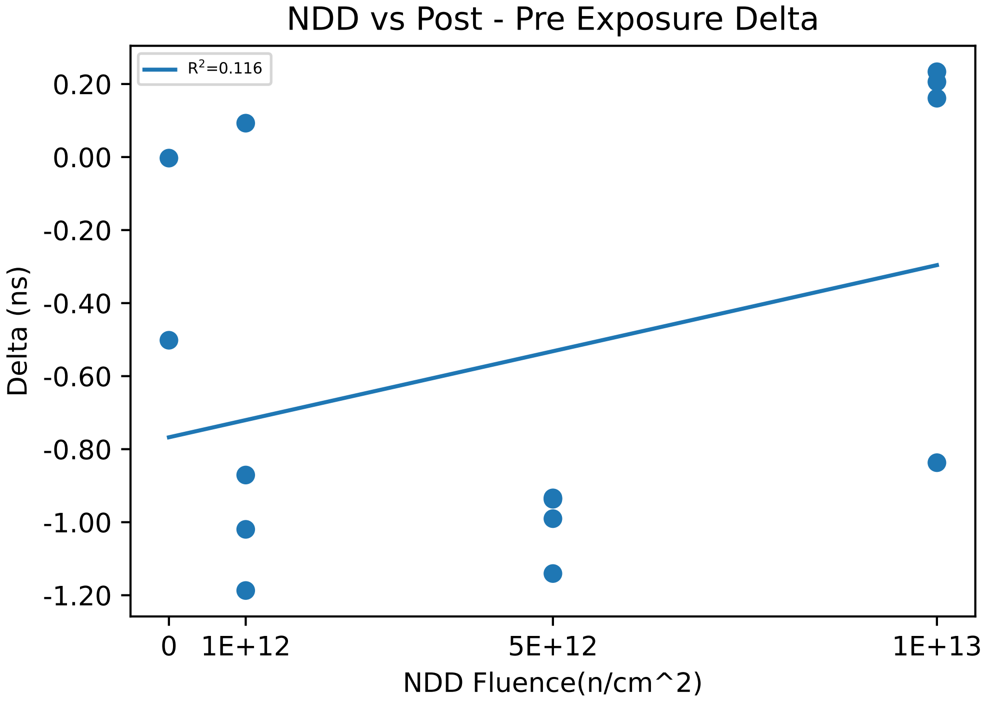
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	11.072	10.603	-0.4688
2	0	Correlation	11.232	10.777	-0.4542
30	1e+12	NDD unbiased	11.153	10.176	-0.9774
31	1e+12	NDD unbiased	11.338	9.8304	-1.5073
32	1e+12	NDD unbiased	11	9.8026	-1.1975
33	1e+12	NDD unbiased	9.8302	9.5772	-0.253
44	5e+12	NDD unbiased	11.185	10.012	-1.1734
45	5e+12	NDD unbiased	11.591	9.905	-1.6857
46	5e+12	NDD unbiased	11.653	10.498	-1.155
47	5e+12	NDD unbiased	11.027	9.9056	-1.1219
50	1e+13	NDD unbiased	9.8314	10.035	0.2033
51	1e+13	NDD unbiased	11.654	10.694	-0.9596
52	1e+13	NDD unbiased	9.9022	9.9178	0.0156
53	1e+13	NDD unbiased	10.599	10.79	0.1904

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	11.072	11.152	11.232	0.11307	10.603	10.69	10.777	0.12339	-0.4688	-0.4615	-0.4542	0.010324
1e+12	9.8302	10.83	11.338	0.68089	9.5772	9.8465	10.176	0.24713	-1.5073	-0.9838	-0.253	0.53349
5e+12	11.027	11.364	11.653	0.30562	9.905	10.08	10.498	0.28322	-1.6857	-1.284	-1.1219	0.26865
1e+13	9.8314	10.497	11.654	0.84561	9.9178	10.359	10.79	0.44626	-0.9596	-0.13758	0.2033	0.55466

Device Test: 97.10 T_RLH_MIN(_DLH Dead Time Min 2MHz VIN_14V)





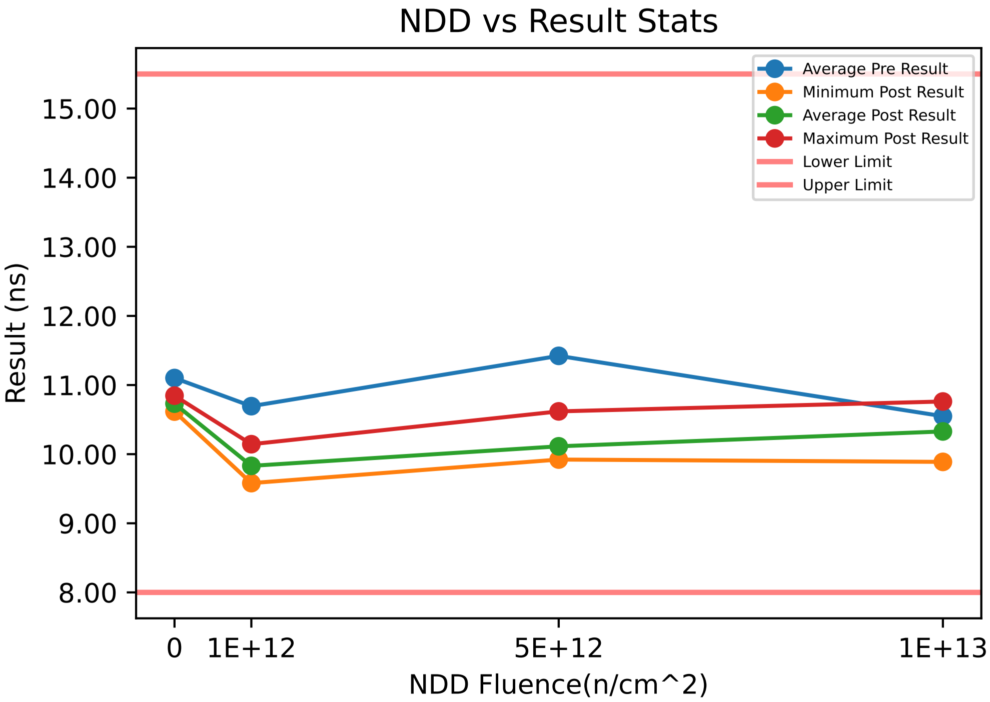
Test Results (Lower Limit = 0.0, Upper Limit = 10.0 (ns))

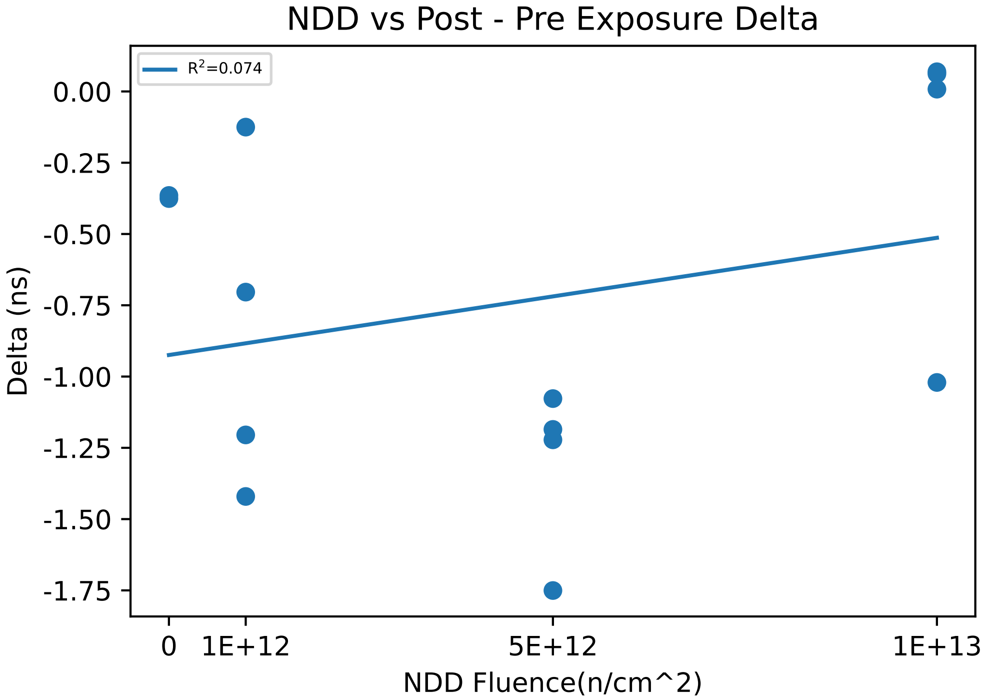
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	4.0538	3.5521	-0.5017
2	0	Correlation	3.7548	3.7519	-0.0029
30	1e+12	NDD unbiased	3.9621	2.775	-1.1871
31	1e+12	NDD unbiased	3.7796	2.9088	-0.8708
32	1e+12	NDD unbiased	3.9472	2.9276	-1.0196
33	1e+12	NDD unbiased	2.051	2.1438	0.0928
44	5e+12	NDD unbiased	3.7028	2.7694	-0.9334
45	5e+12	NDD unbiased	4.0895	3.0992	-0.9903
46	5e+12	NDD unbiased	4.1938	3.2566	-0.9372
47	5e+12	NDD unbiased	4.2225	3.0819	-1.1406
50	1e+13	NDD unbiased	2.6372	2.7983	0.1611
51	1e+13	NDD unbiased	4.7113	3.8743	-0.837
52	1e+13	NDD unbiased	2.8738	3.1074	0.2336
53	1e+13	NDD unbiased	3.2844	3.4903	0.2059

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.7548	3.9043	4.0538	0.21142	3.5521	3.652	3.7519	0.14128	-0.5017	-0.2523	-0.0029	0.3527
1e+12	2.051	3.435	3.9621	0.92635	2.1438	2.6888	2.9276	0.36963	-1.1871	-0.74618	0.0928	0.57405
5e+12	3.7028	4.0522	4.2225	0.23981	2.7694	3.0518	3.2566	0.204	-1.1406	-1.0004	-0.9334	0.097025
1e+13	2.6372	3.3767	4.7113	0.92906	2.7983	3.3176	3.8743	0.46676	-0.837	-0.0591	0.2336	0.51946

Device Test: 97.11 T_RLH_SMALL(_DLH Dead Time Small 2MHz VIN_14V)





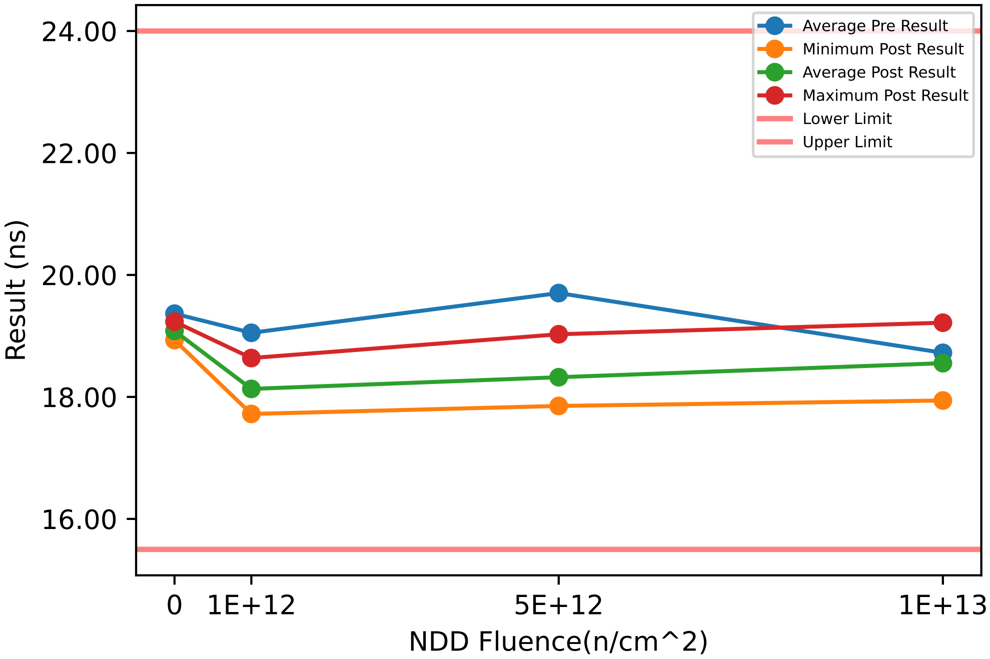
Test Results (Lower Limit = 8.0, Upper Limit = 15.5 (ns))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	10.992	10.616	-0.3757
2	0	Correlation	11.211	10.846	-0.3648
30	1e+12	NDD unbiased	10.848	10.144	-0.7038
31	1e+12	NDD unbiased	11.19	9.7694	-1.4206
32	1e+12	NDD unbiased	11.034	9.8289	-1.2047
33	1e+12	NDD unbiased	9.7062	9.5811	-0.1251
44	5e+12	NDD unbiased	11.17	9.985	-1.1854
45	5e+12	NDD unbiased	11.679	9.9281	-1.7505
46	5e+12	NDD unbiased	11.696	10.619	-1.0773
47	5e+12	NDD unbiased	11.144	9.922	-1.2219
50	1e+13	NDD unbiased	9.9325	10.002	0.0691
51	1e+13	NDD unbiased	11.684	10.663	-1.0207
52	1e+13	NDD unbiased	9.8802	9.8882	0.008
53	1e+13	NDD unbiased	10.7	10.762	0.062

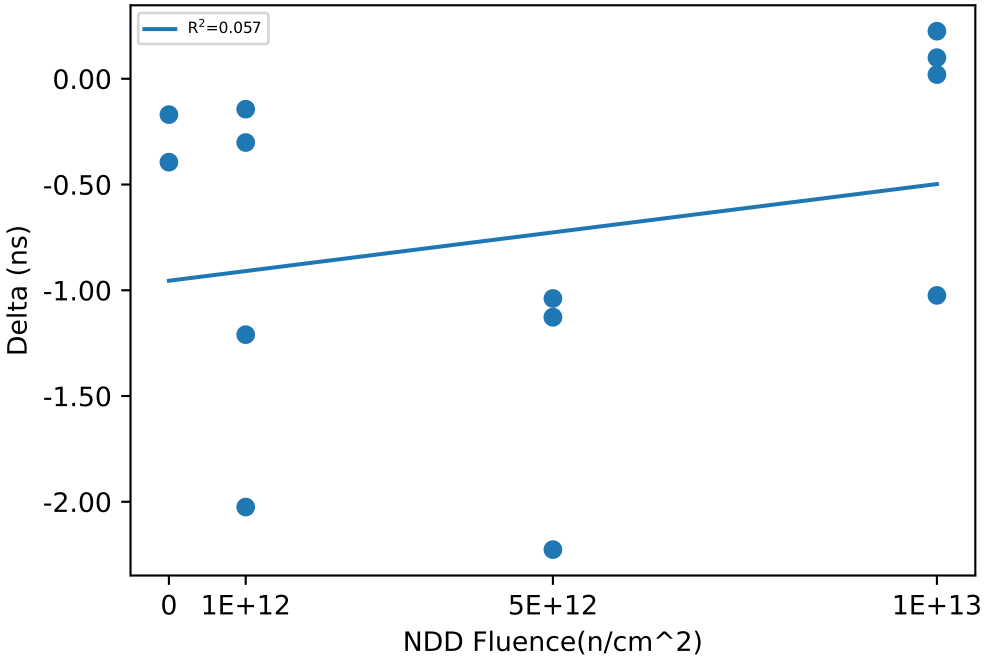
Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	10.992	11.101	11.211	0.15521	10.616	10.731	10.846	0.16292	-0.3757	-0.37025	-0.3648	0.0077075
1e+12	9.7062	10.694	11.19	0.67349	9.5811	9.8308	10.144	0.23396	-1.4206	-0.86355	-0.1251	0.57663
5e+12	11.144	11.422	11.696	0.30642	9.922	10.114	10.619	0.33813	-1.7505	-1.3088	-1.0773	0.30082
1e+13	9.8802	10.549	11.684	0.84404	9.8882	10.329	10.762	0.4473	-1.0207	-0.2204	0.0691	0.53423

Device Test: 97.12 T_RLH_MID(_DLH Dead Time Mid 2MHz VIN_14V)



NDD vs Result Stats



NDD vs Post - Pre Exposure Delta

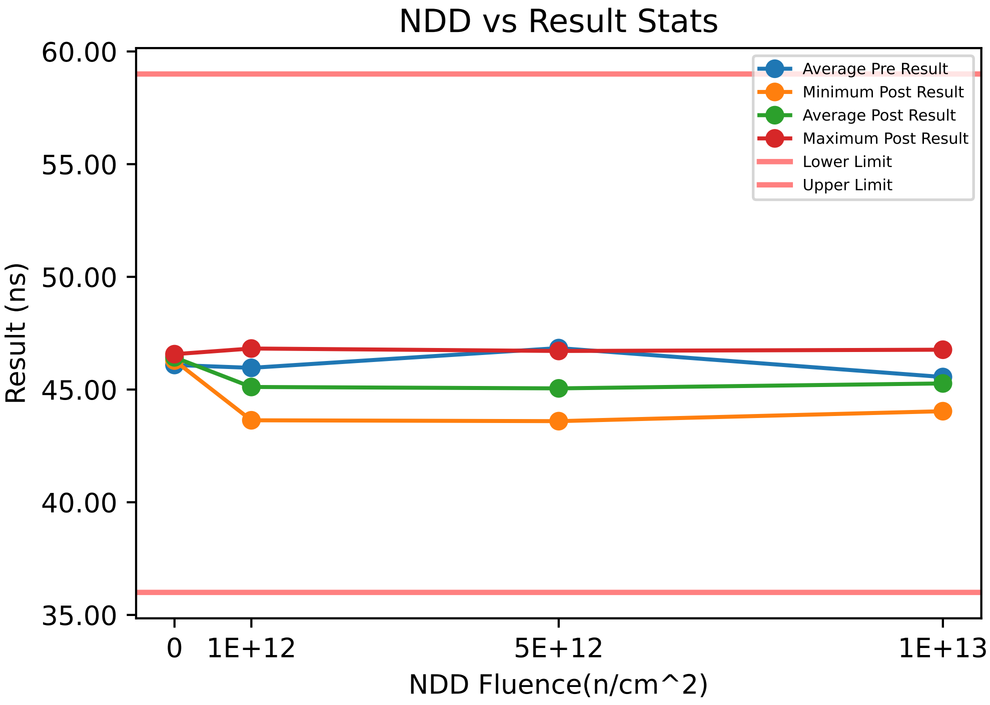
Test Results (Lower Limit = 15.5, Upper Limit = 24.0 (ns))

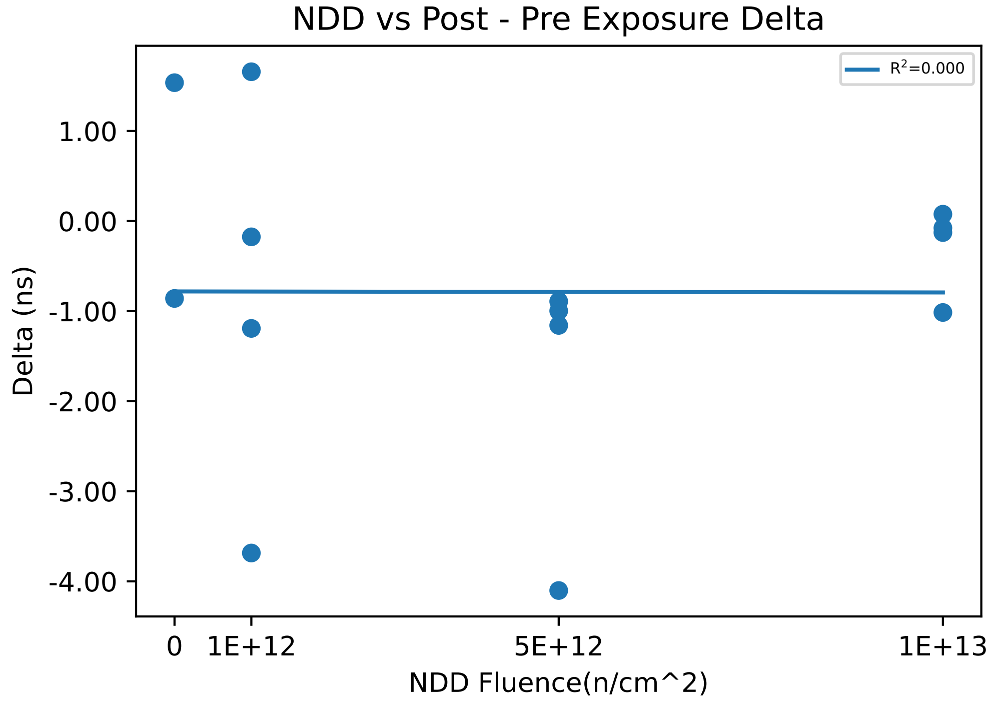
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	19.102	18.933	-0.1695
2	0	Correlation	19.629	19.234	-0.3944
30	1e+12	NDD unbiased	18.939	18.638	-0.3015
31	1e+12	NDD unbiased	19.746	17.721	-2.0249
32	1e+12	NDD unbiased	19	17.79	-1.2099
33	1e+12	NDD unbiased	18.522	18.378	-0.1437
44	5e+12	NDD unbiased	19.562	18.523	-1.0387
45	5e+12	NDD unbiased	20.116	17.89	-2.2261
46	5e+12	NDD unbiased	20.154	19.027	-1.1268
47	5e+12	NDD unbiased	18.98	17.852	-1.1277
50	1e+13	NDD unbiased	18.347	18.447	0.0998
51	1e+13	NDD unbiased	19.633	18.608	-1.0242
52	1e+13	NDD unbiased	17.922	17.941	0.0197
53	1e+13	NDD unbiased	18.992	19.217	0.2249

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	19.102	19.365	19.629	0.37243	18.933	19.083	19.234	0.2134	-0.3944	-0.28195	-0.1695	0.15903
1e+12	18.522	19.052	19.746	0.50932	17.721	18.132	18.638	0.44805	-2.0249	-0.92	-0.1437	0.8737
5e+12	18.98	19.703	20.154	0.55281	17.852	18.323	19.027	0.56144	-2.2261	-1.3798	-1.0387	0.56573
1e+13	17.922	18.723	19.633	0.74907	17.941	18.553	19.217	0.52578	-1.0242	-0.16995	0.2249	0.57573

Device Test: 97.13 T_RLH_LARGE(_DLH Dead Time Large 2MHz VIN_14V)





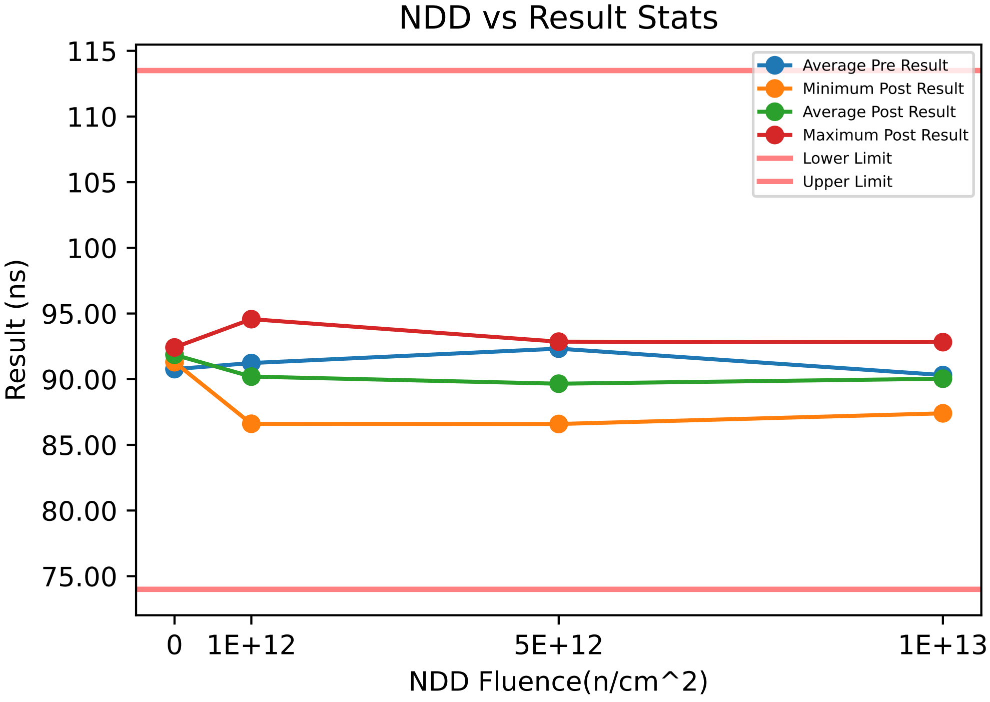
Test Results (Lower Limit = 36.0, Upper Limit = 59.0 (ns))

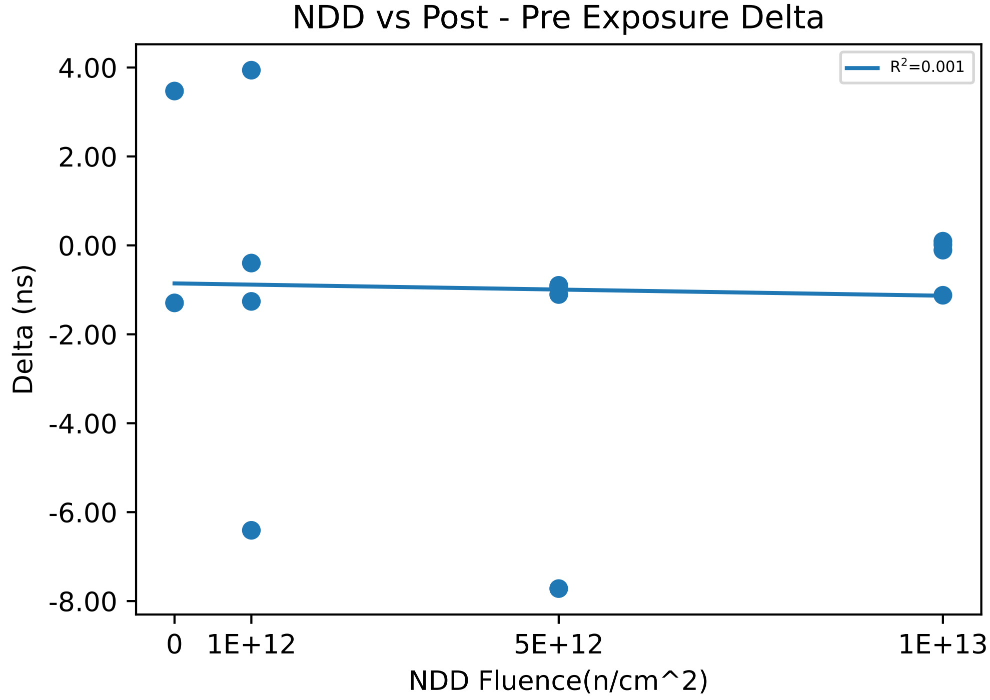
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	44.752	46.288	1.5365
2	0	Correlation	47.429	46.569	-0.8592
30	1e+12	NDD unbiased	44.653	46.311	1.6579
31	1e+12	NDD unbiased	47.373	43.688	-3.6853
32	1e+12	NDD unbiased	44.828	43.636	-1.1917
33	1e+12	NDD unbiased	46.995	46.821	-0.175
44	5e+12	NDD unbiased	47.293	46.296	-0.9972
45	5e+12	NDD unbiased	47.705	43.603	-4.1018
46	5e+12	NDD unbiased	47.603	46.712	-0.8919
47	5e+12	NDD unbiased	44.756	43.598	-1.1585
50	1e+13	NDD unbiased	46.114	45.987	-0.1273
51	1e+13	NDD unbiased	45.304	44.29	-1.0148
52	1e+13	NDD unbiased	44.116	44.039	-0.0768
53	1e+13	NDD unbiased	46.691	46.767	0.0763

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	44.752	46.09	47.429	1.8929	46.288	46.429	46.569	0.19884	-0.8592	0.33865	1.5365	1.694
1e+12	44.653	45.963	47.373	1.4211	43.636	45.114	46.821	1.6893	-3.6853	-0.84852	1.6579	2.2287
5e+12	44.756	46.839	47.705	1.3997	43.598	45.052	46.712	1.6847	-4.1018	-1.7873	-0.8919	1.5469
1e+13	44.116	45.557	46.691	1.1162	44.039	45.271	46.767	1.3207	-1.0148	-0.28565	0.0763	0.49375

Device Test: 97.14 T_RLH_MAX(_DLH Dead Time Max 2MHz VIN_14V)





Test Results (Lower Limit = 74.0, Upper Limit = 113.5 (ns))

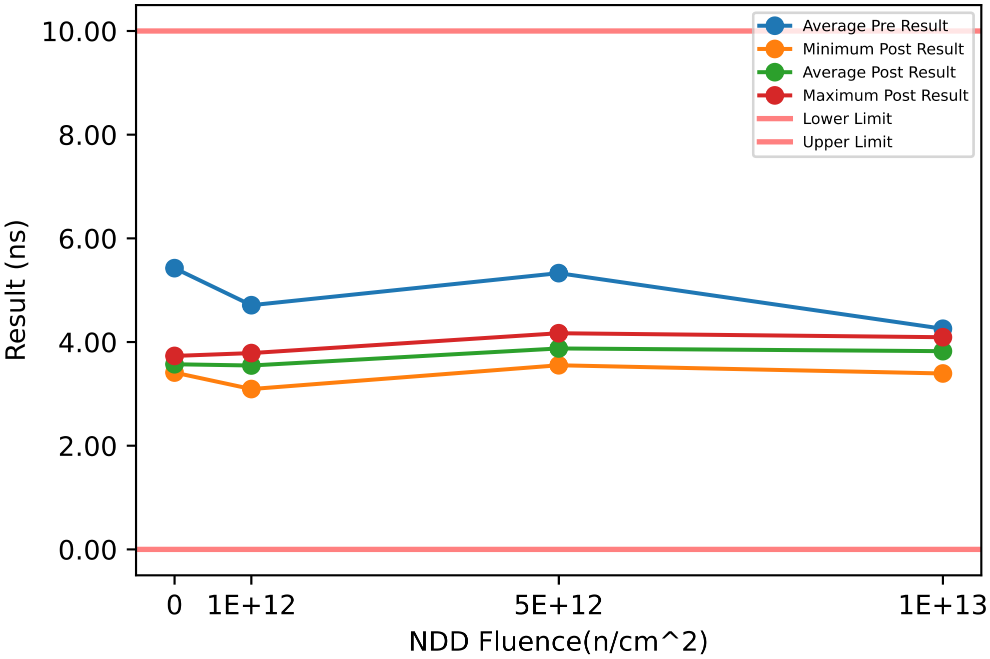
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	87.825	91.296	3.4709
2	0	Correlation	93.71	92.416	-1.2938
30	1e+12	NDD unbiased	88.481	92.421	3.9395
31	1e+12	NDD unbiased	93.6	87.191	-6.4085
32	1e+12	NDD unbiased	87.864	86.604	-1.2603
33	1e+12	NDD unbiased	94.969	94.571	-0.3979
44	5e+12	NDD unbiased	93.479	92.581	-0.8987
45	5e+12	NDD unbiased	94.319	86.599	-7.7193
46	5e+12	NDD unbiased	93.81	92.856	-0.9543
47	5e+12	NDD unbiased	87.694	86.588	-1.1058
50	1e+13	NDD unbiased	91.901	91.793	-0.1075
51	1e+13	NDD unbiased	88.523	87.401	-1.122
52	1e+13	NDD unbiased	88.106	88.122	0.016
53	1e+13	NDD unbiased	92.727	92.821	0.0938

Test Statistics (ns)

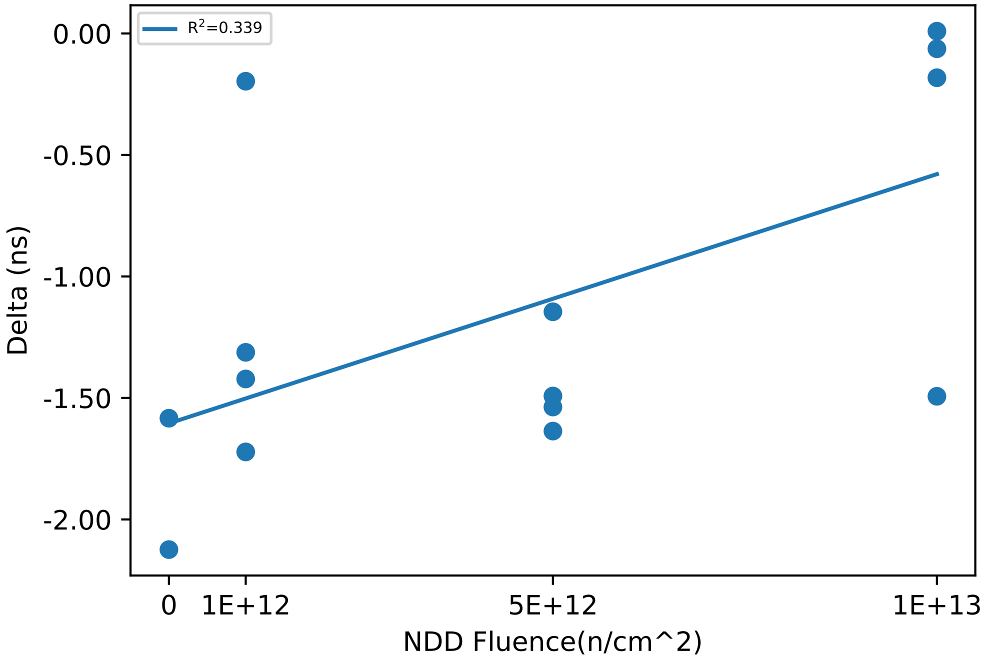
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	87.825	90.768	93.71	4.1611	91.296	91.856	92.416	0.79196	-1.2938	1.0886	3.4709	3.3692
1e+12	87.864	91.228	94.969	3.5814	86.604	90.197	94.571	3.9165	-6.4085	-1.0318	3.9395	4.2457
5e+12	87.694	92.325	94.319	3.1068	86.588	89.656	92.856	3.5377	-7.7193	-2.6695	-0.8987	3.3677
1e+13	88.106	90.314	92.727	2.34	87.401	90.034	92.821	2.6742	-1.122	-0.27992	0.0938	0.56747

Device Test: 97.19 T_RHL_MIN(_DHL Dead Time Min 500kHz VIN_14V)

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



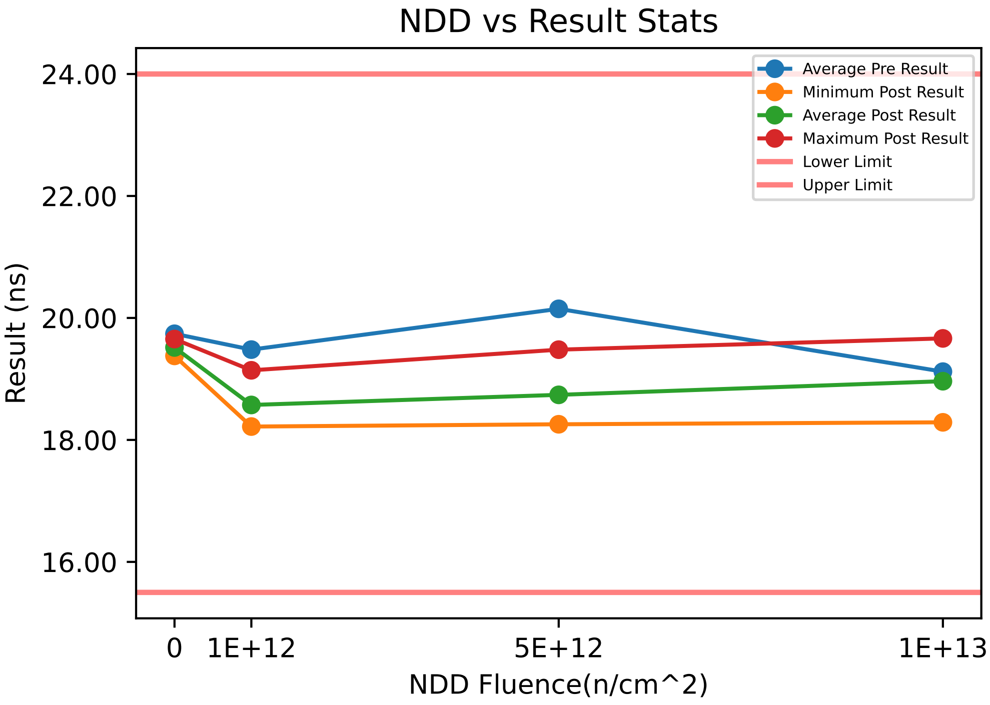
Test Results (Lower Limit = 0.0, Upper Limit = 10.0 (ns))

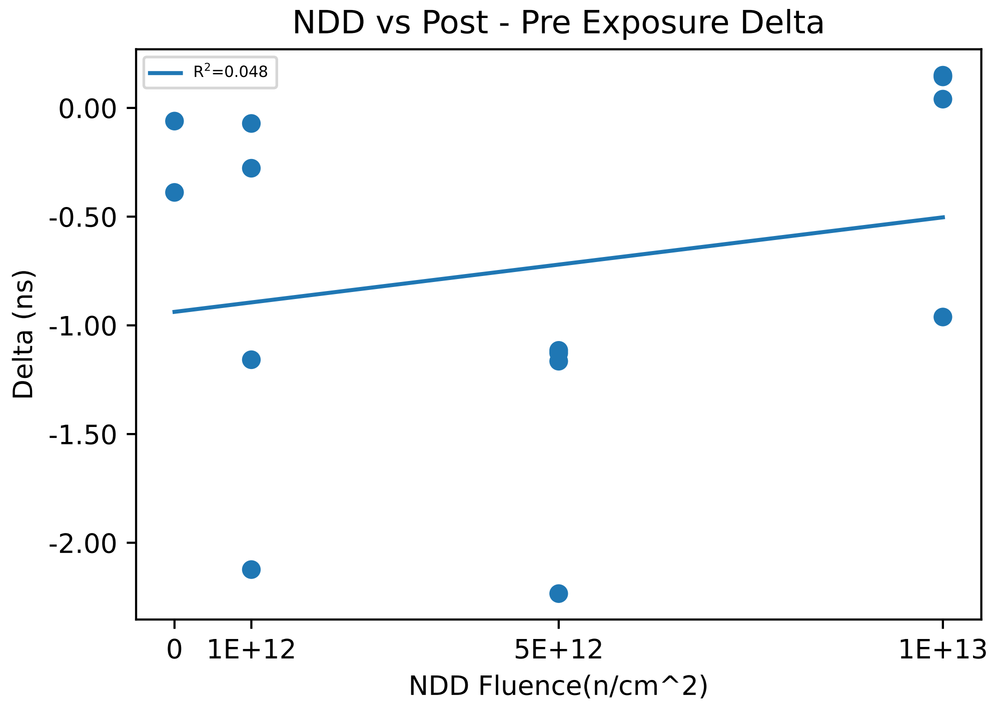
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	5.3153	3.7319	-1.5834
2	0	Correlation	5.5352	3.4111	-2.1241
30	1e+12	NDD unbiased	5.2753	3.5532	-1.7221
31	1e+12	NDD unbiased	5.0992	3.7869	-1.3123
32	1e+12	NDD unbiased	4.5152	3.0933	-1.4219
33	1e+12	NDD unbiased	3.9526	3.756	-0.1966
44	5e+12	NDD unbiased	5.7071	4.1698	-1.5373
45	5e+12	NDD unbiased	5.0302	3.8848	-1.1454
46	5e+12	NDD unbiased	5.1884	3.552	-1.6364
47	5e+12	NDD unbiased	5.3905	3.8984	-1.4921
50	1e+13	NDD unbiased	3.3843	3.3936	0.0093
51	1e+13	NDD unbiased	5.5862	4.093	-1.4932
52	1e+13	NDD unbiased	4.1232	3.941	-0.1822
53	1e+13	NDD unbiased	3.9317	3.8687	-0.063

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.3153	5.4253	5.5352	0.15549	3.4111	3.5715	3.7319	0.22684	-2.1241	-1.8537	-1.5834	0.38233
1e+12	3.9526	4.7106	5.2753	0.60073	3.0933	3.5473	3.7869	0.31996	-1.7221	-1.1632	-0.1966	0.66729
5e+12	5.0302	5.329	5.7071	0.292	3.552	3.8763	4.1698	0.2529	-1.6364	-1.4528	-1.1454	0.21361
1e+13	3.3843	4.2563	5.5862	0.94023	3.3936	3.8241	4.093	0.30182	-1.4932	-0.43227	0.0093	0.71168

Device Test: 97.2 T_RLH_MID(_DLH Dead Time Mid 500kHz VIN_14V)





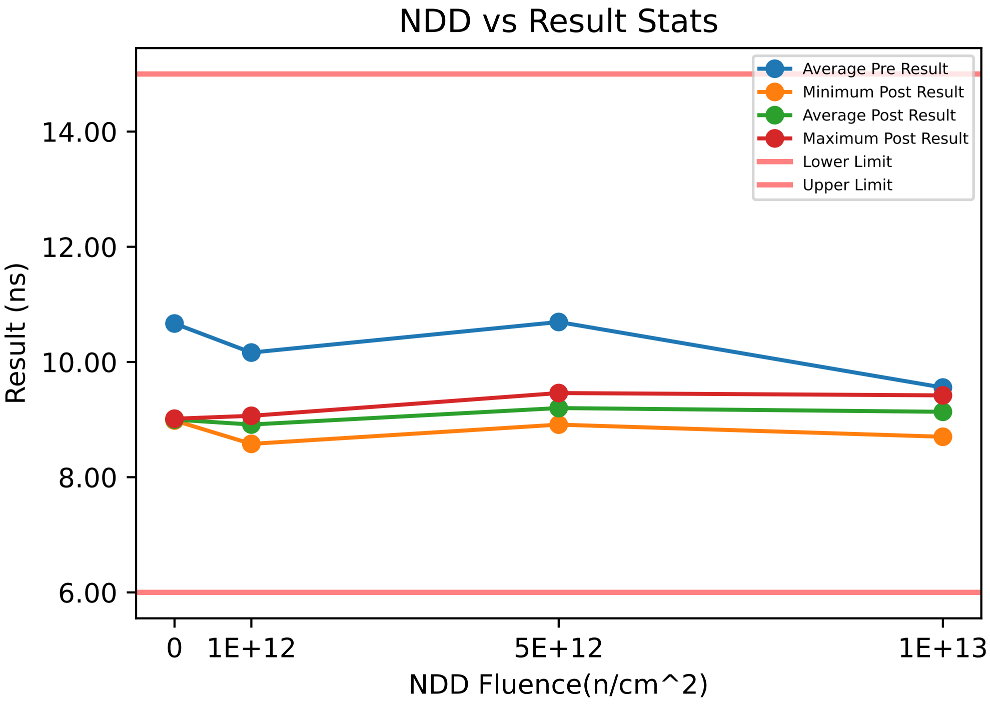
Test Results (Lower Limit = 15.5, Upper Limit = 24.0 (ns))

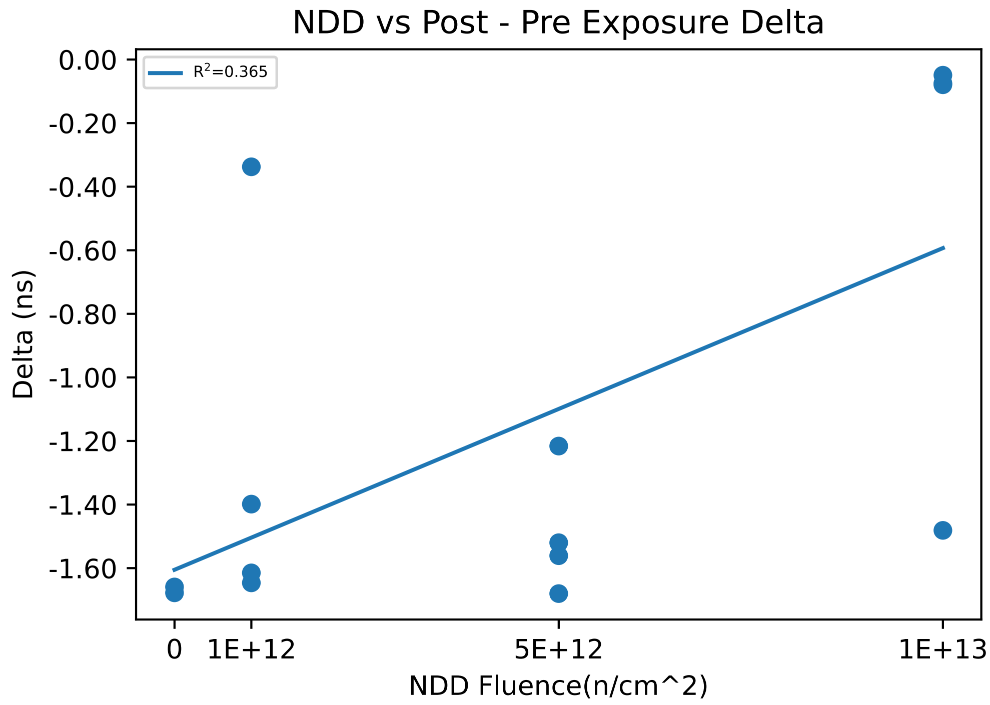
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	19.439	19.378	-0.0605
2	0	Correlation	20.043	19.654	-0.3885
30	1e+12	NDD unbiased	19.419	19.142	-0.2773
31	1e+12	NDD unbiased	20.343	18.219	-2.1233
32	1e+12	NDD unbiased	19.387	18.229	-1.1581
33	1e+12	NDD unbiased	18.776	18.704	-0.0714
44	5e+12	NDD unbiased	20.116	18.951	-1.1649
45	5e+12	NDD unbiased	20.503	18.269	-2.2338
46	5e+12	NDD unbiased	20.595	19.48	-1.115
47	5e+12	NDD unbiased	19.384	18.257	-1.1278
50	1e+13	NDD unbiased	18.748	18.899	0.1506
51	1e+13	NDD unbiased	19.96	18.998	-0.9616
52	1e+13	NDD unbiased	18.248	18.289	0.0405
53	1e+13	NDD unbiased	19.522	19.665	0.1428

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	19.439	19.741	20.043	0.42709	19.378	19.516	19.654	0.19516	-0.3885	-0.2245	-0.0605	0.23193
1e+12	18.776	19.481	20.343	0.6462	18.219	18.573	19.142	0.44124	-2.1233	-0.90753	-0.0714	0.93758
5e+12	19.384	20.15	20.595	0.55072	18.257	18.739	19.48	0.59081	-2.2338	-1.4104	-1.115	0.54936
1e+13	18.248	19.12	19.96	0.7671	18.289	18.963	19.665	0.56349	-0.9616	-0.15693	0.1506	0.53879

Device Test: 97.20 T_RHL_SMALL(_DHL Dead Time Small 500kHz VIN_14V)





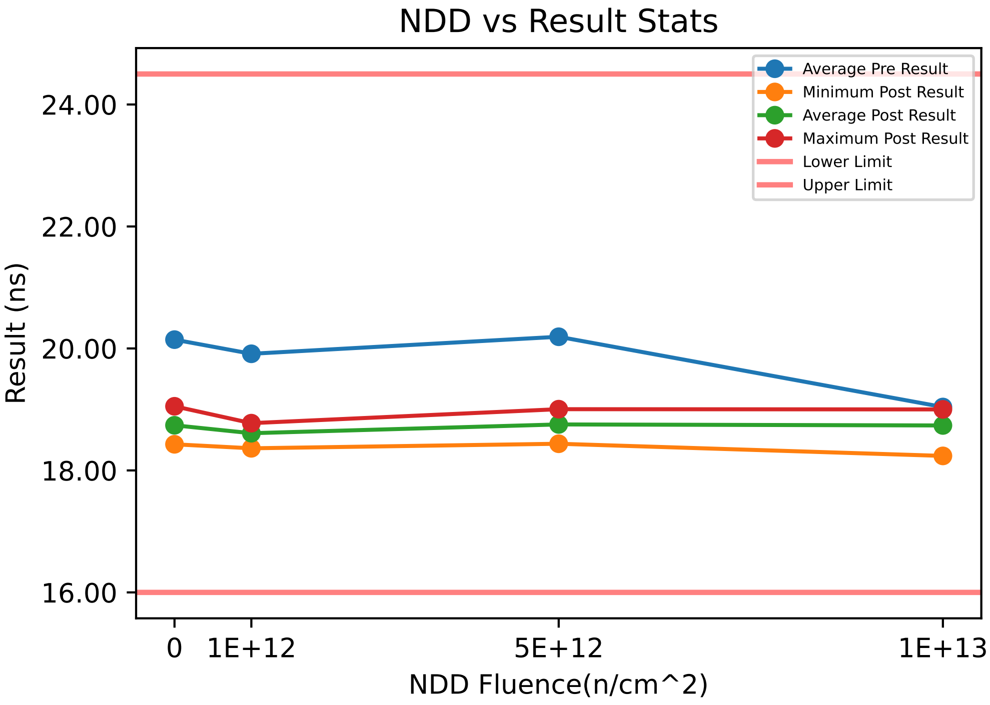
Test Results (Lower Limit = 6.0, Upper Limit = 15.0 (ns))

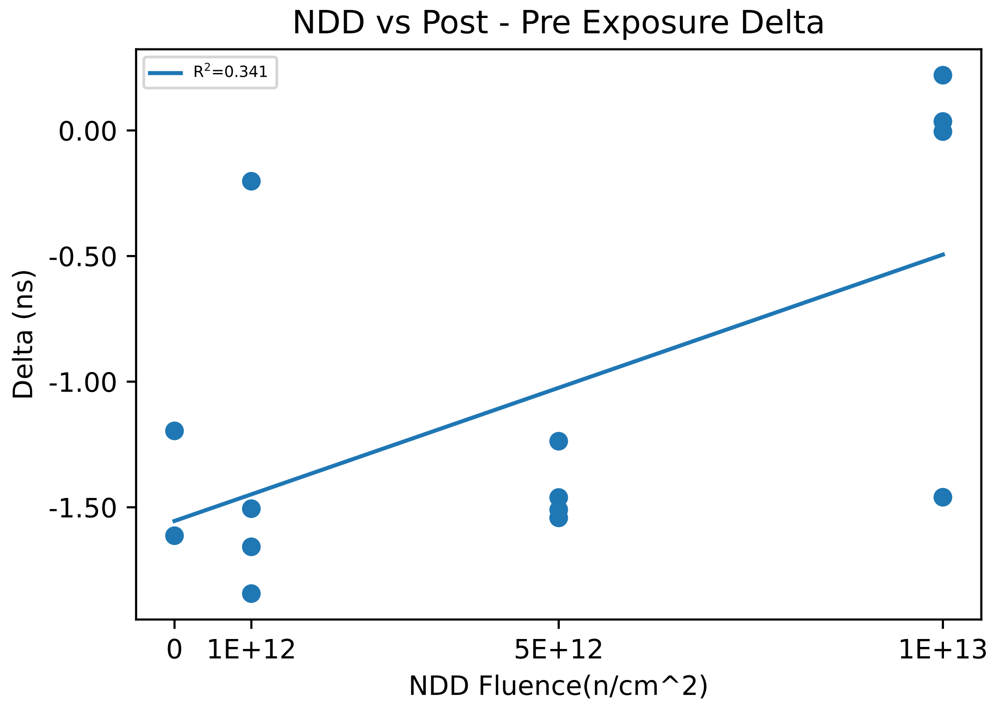
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	10.643	8.9839	-1.6592
2	0	Correlation	10.693	9.0154	-1.6777
30	1e+12	NDD unbiased	10.615	8.9686	-1.6463
31	1e+12	NDD unbiased	10.464	9.0657	-1.3986
32	1e+12	NDD unbiased	10.193	8.5785	-1.6149
33	1e+12	NDD unbiased	9.3825	9.045	-0.3375
44	5e+12	NDD unbiased	11.141	9.4609	-1.6801
45	5e+12	NDD unbiased	10.435	9.2193	-1.216
46	5e+12	NDD unbiased	10.433	8.9126	-1.52
47	5e+12	NDD unbiased	10.769	9.2084	-1.5609
50	1e+13	NDD unbiased	8.7511	8.7018	-0.0493
51	1e+13	NDD unbiased	10.902	9.4207	-1.4812
52	1e+13	NDD unbiased	9.3511	9.2717	-0.0794
53	1e+13	NDD unbiased	9.2217	9.1471	-0.0746

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	10.643	10.668	10.693	0.035355	8.9839	8.9996	9.0154	0.022274	-1.6777	-1.6684	-1.6592	0.013081
1e+12	9.3825	10.164	10.615	0.54927	8.5785	8.9145	9.0657	0.22783	-1.6463	-1.2493	-0.3375	0.61778
5e+12	10.433	10.695	11.141	0.33701	8.9126	9.2003	9.4609	0.22443	-1.6801	-1.4943	-1.216	0.19754
1e+13	8.7511	9.5564	10.902	0.93328	8.7018	9.1353	9.4207	0.3099	-1.4812	-0.42112	-0.0493	0.70684

Device Test: 97.21 T_RHL_MID(_DHL Dead Time Mid 500kHz VIN_14V)





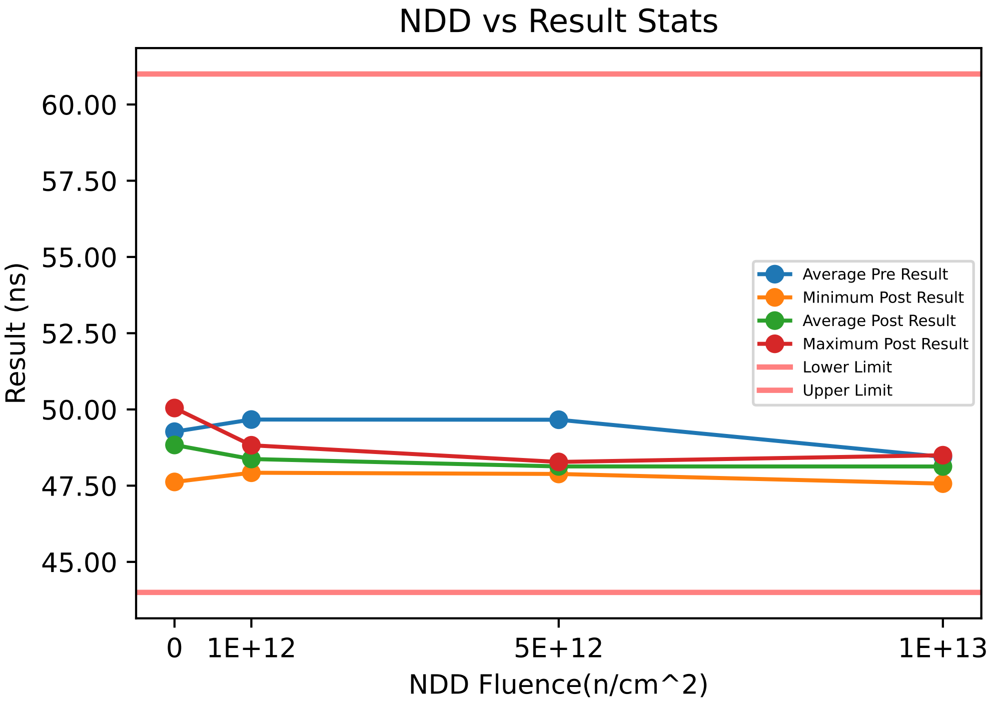
Test Results (Lower Limit = 16.0, Upper Limit = 24.5 (ns))

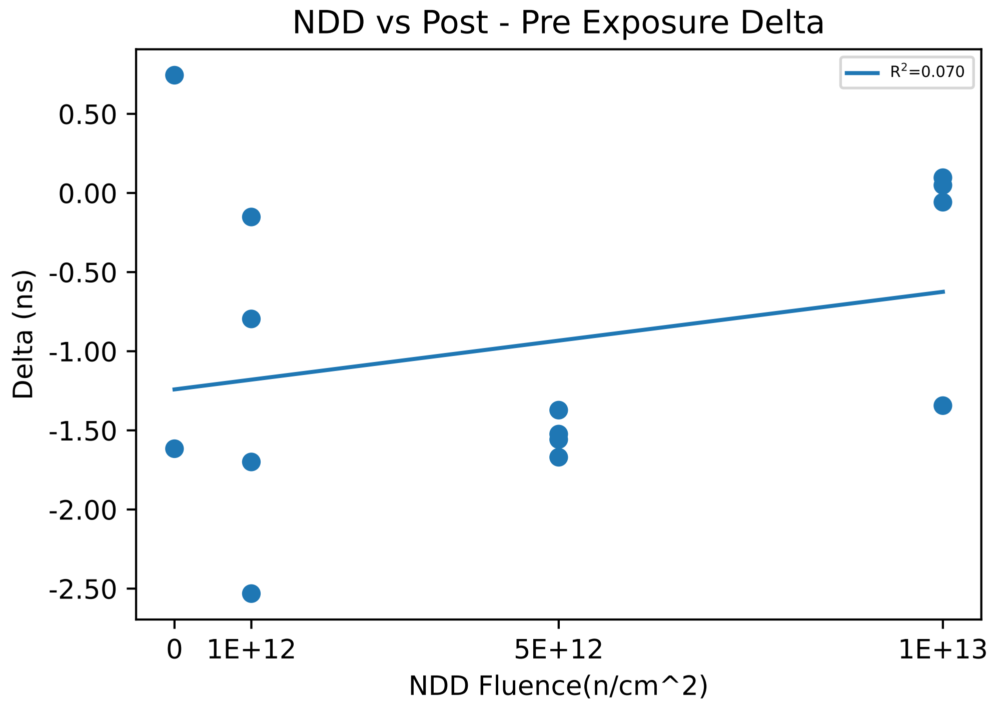
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	20.042	18.428	-1.6132
2	0	Correlation	20.247	19.052	-1.1959
30	1e+12	NDD unbiased	20.28	18.775	-1.5056
31	1e+12	NDD unbiased	20.511	18.667	-1.8436
32	1e+12	NDD unbiased	20.02	18.363	-1.6574
33	1e+12	NDD unbiased	18.838	18.636	-0.2022
44	5e+12	NDD unbiased	20.514	19.004	-1.5099
45	5e+12	NDD unbiased	20	18.763	-1.237
46	5e+12	NDD unbiased	19.98	18.437	-1.5422
47	5e+12	NDD unbiased	20.273	18.812	-1.4611
50	1e+13	NDD unbiased	18.202	18.238	0.0357
51	1e+13	NDD unbiased	20.46	19	-1.46
52	1e+13	NDD unbiased	18.948	18.944	-0.0045
53	1e+13	NDD unbiased	18.547	18.767	0.2199

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	20.042	20.145	20.247	0.14552	18.428	18.74	19.052	0.4406	-1.6132	-1.4045	-1.1959	0.29508
1e+12	18.838	19.912	20.511	0.74351	18.363	18.61	18.775	0.17534	-1.8436	-1.3022	-0.2022	0.74625
5e+12	19.98	20.192	20.514	0.2531	18.437	18.754	19.004	0.23545	-1.5422	-1.4375	-1.237	0.13779
1e+13	18.202	19.04	20.46	0.99503	18.238	18.737	19	0.34735	-1.46	-0.30223	0.2199	0.77801

Device Test: 97.22 T_RHL_LARGE(_DHL Dead Time Large 500kHz VIN_14V)


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

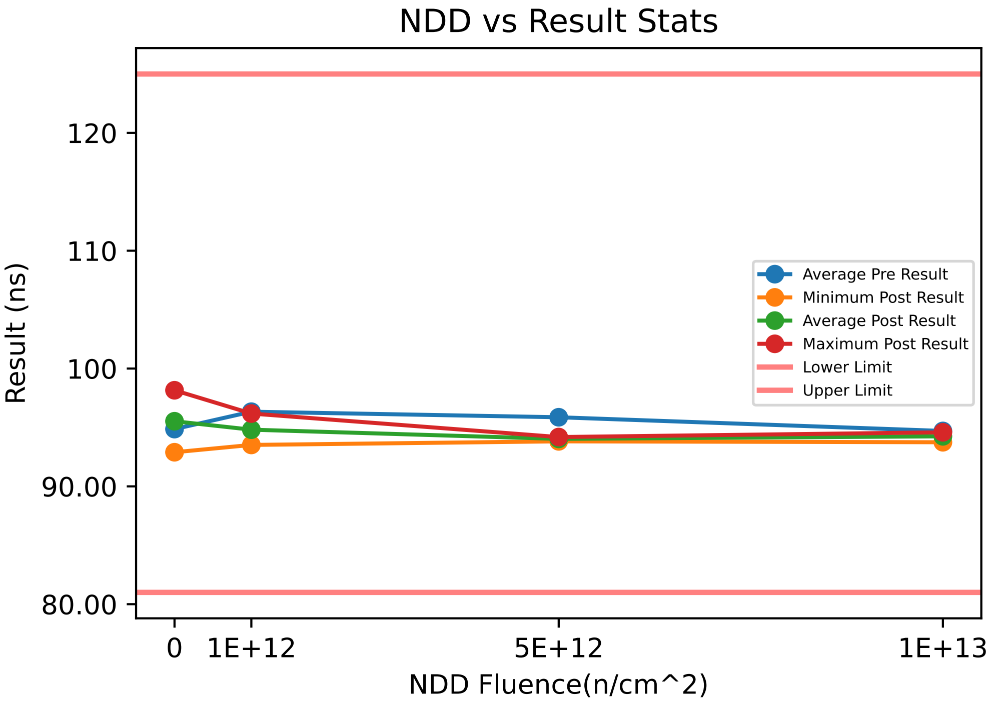
Test Results (Lower Limit = 44.0, Upper Limit = 61.0 (ns))

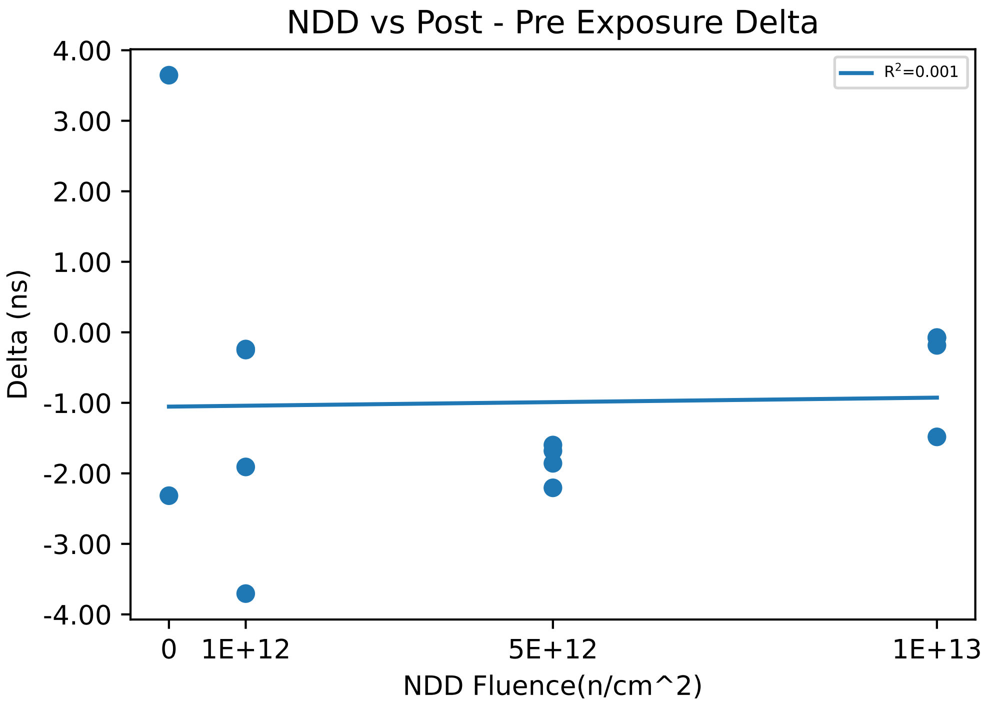
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	49.239	47.623	-1.616
2	0	Correlation	49.302	50.047	0.7443
30	1e+12	NDD unbiased	49.621	48.825	-0.7958
31	1e+12	NDD unbiased	50.653	48.121	-2.5315
32	1e+12	NDD unbiased	50.325	48.625	-1.6996
33	1e+12	NDD unbiased	48.076	47.924	-0.1517
44	5e+12	NDD unbiased	49.65	48.278	-1.3722
45	5e+12	NDD unbiased	49.711	48.153	-1.5578
46	5e+12	NDD unbiased	49.554	47.884	-1.6699
47	5e+12	NDD unbiased	49.733	48.209	-1.5235
50	1e+13	NDD unbiased	47.517	47.566	0.049
51	1e+13	NDD unbiased	49.842	48.499	-1.3437
52	1e+13	NDD unbiased	48.349	48.291	-0.0583
53	1e+13	NDD unbiased	48.064	48.16	0.0967

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	49.239	49.27	49.302	0.045113	47.623	48.835	50.047	1.7141	-1.616	-0.43585	0.7443	1.669
1e+12	48.076	49.669	50.653	1.1459	47.924	48.374	48.825	0.42139	-2.5315	-1.2946	-0.1517	1.0407
5e+12	49.554	49.662	49.733	0.079947	47.884	48.131	48.278	0.17238	-1.6699	-1.5309	-1.3722	0.12286
1e+13	47.517	48.443	49.842	0.99459	47.566	48.129	48.499	0.40011	-1.3437	-0.31408	0.0967	0.68947

Device Test: 97.23 T_RHL_MAX(_DHL Dead Time Max 500kHz VIN_14V)





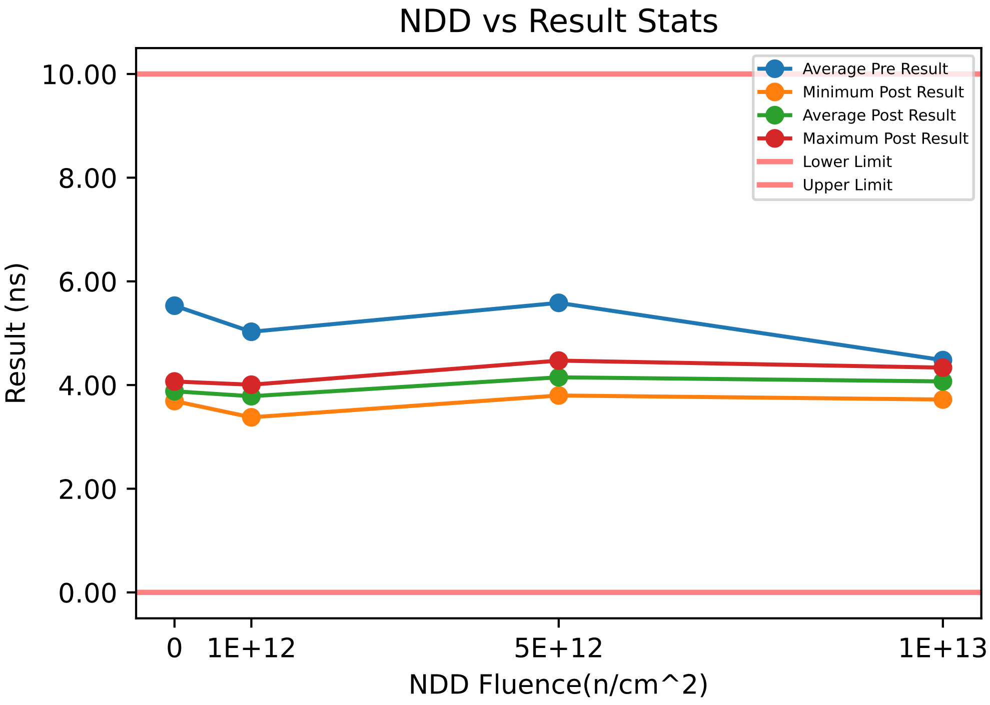
Test Results (Lower Limit = 81.0, Upper Limit = 125.0 (ns))

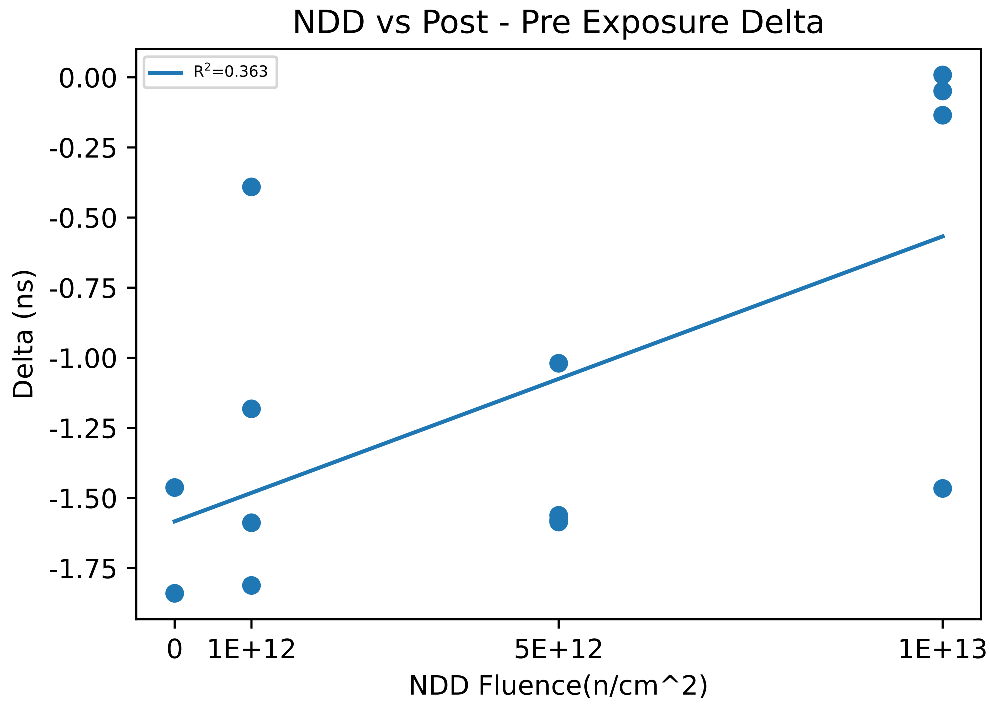
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	95.213	92.896	-2.3168
2	0	Correlation	94.51	98.156	3.6462
30	1e+12	NDD unbiased	95.759	95.522	-0.2368
31	1e+12	NDD unbiased	97.731	94.026	-3.7052
32	1e+12	NDD unbiased	98.09	96.181	-1.909
33	1e+12	NDD unbiased	93.769	93.517	-0.2514
44	5e+12	NDD unbiased	95.419	93.821	-1.5985
45	5e+12	NDD unbiased	96.391	94.186	-2.2052
46	5e+12	NDD unbiased	95.827	93.969	-1.8578
47	5e+12	NDD unbiased	95.825	94.144	-1.6811
50	1e+13	NDD unbiased	93.822	93.744	-0.0779
51	1e+13	NDD unbiased	95.962	94.479	-1.4828
52	1e+13	NDD unbiased	94.367	94.182	-0.1852
53	1e+13	NDD unbiased	94.661	94.588	-0.0737

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	94.51	94.862	95.213	0.49681	92.896	95.526	98.156	3.7197	-2.3168	0.6647	3.6462	4.2165
1e+12	93.769	96.337	98.09	1.9958	93.517	94.812	96.181	1.2482	-3.7052	-1.5256	-0.2368	1.6515
5e+12	95.419	95.866	96.391	0.39911	93.821	94.03	94.186	0.16792	-2.2052	-1.8356	-1.5985	0.26906
1e+13	93.822	94.703	95.962	0.90854	93.744	94.248	94.588	0.3774	-1.4828	-0.4549	-0.0737	0.68721

Device Test: 97.24 T_RHL_MIN(_DHL Dead Time Min 1MHz VIN_14V)





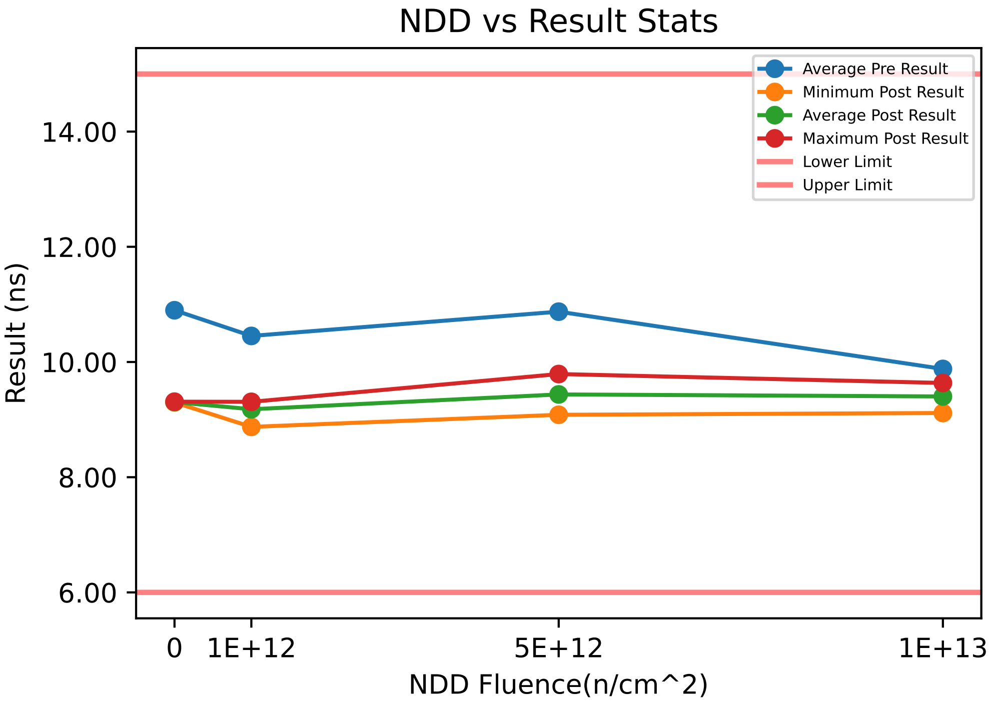
Test Results (Lower Limit = 0.0, Upper Limit = 10.0 (ns))

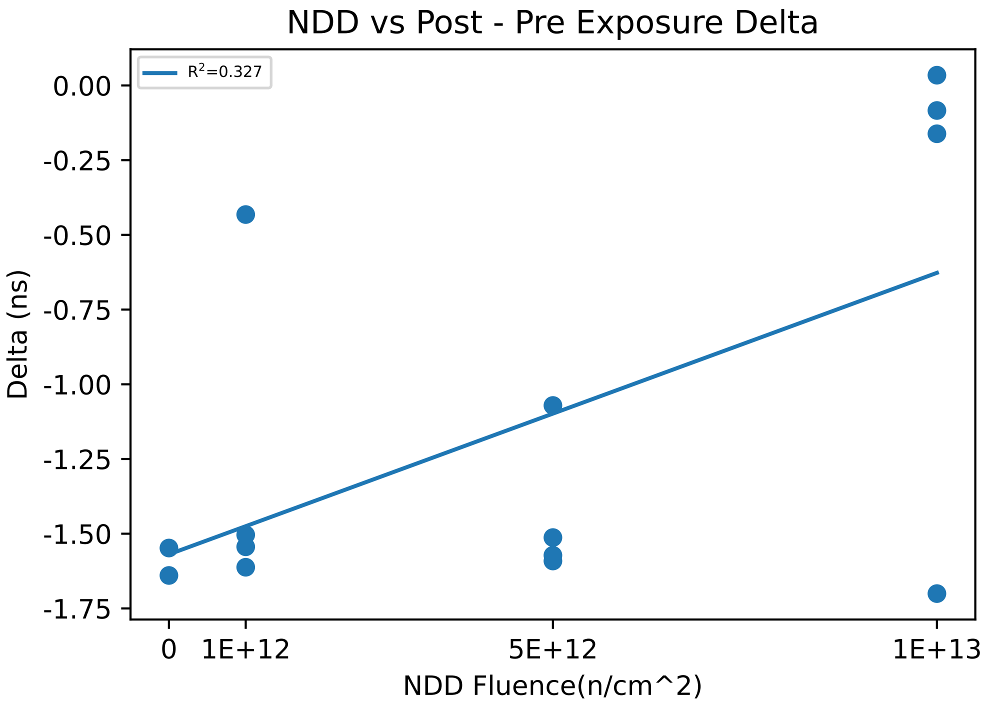
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	5.5312	4.0686	-1.4626
2	0	Correlation	5.5306	3.6907	-1.8399
30	1e+12	NDD unbiased	5.5866	3.7748	-1.8118
31	1e+12	NDD unbiased	5.1884	4.0064	-1.182
32	1e+12	NDD unbiased	4.9656	3.3774	-1.5882
33	1e+12	NDD unbiased	4.3696	3.9789	-0.3907
44	5e+12	NDD unbiased	6.0333	4.4715	-1.5618
45	5e+12	NDD unbiased	5.1678	4.1482	-1.0196
46	5e+12	NDD unbiased	5.384	3.7983	-1.5857
47	5e+12	NDD unbiased	5.7566	4.1785	-1.5781
50	1e+13	NDD unbiased	3.8556	3.7205	-0.1351
51	1e+13	NDD unbiased	5.8018	4.3359	-1.4659
52	1e+13	NDD unbiased	4.2323	4.1834	-0.0489
53	1e+13	NDD unbiased	4.0325	4.041	0.0085

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.5306	5.5309	5.5312	0.00042426	3.6907	3.8796	4.0686	0.26722	-1.8399	-1.6512	-1.4626	0.26679
1e+12	4.3696	5.0275	5.5866	0.50831	3.3774	3.7844	4.0064	0.29032	-1.8118	-1.2432	-0.3907	0.62526
5e+12	5.1678	5.5854	6.0333	0.38509	3.7983	4.1491	4.4715	0.2756	-1.5857	-1.4363	-1.0196	0.27798
1e+13	3.8556	4.4806	5.8018	0.89417	3.7205	4.0702	4.3359	0.2624	-1.4659	-0.41035	0.0085	0.70617

Device Test: 97.25 T_RHL_SMALL(_DHL Dead Time Small 1MHz VIN_14V)





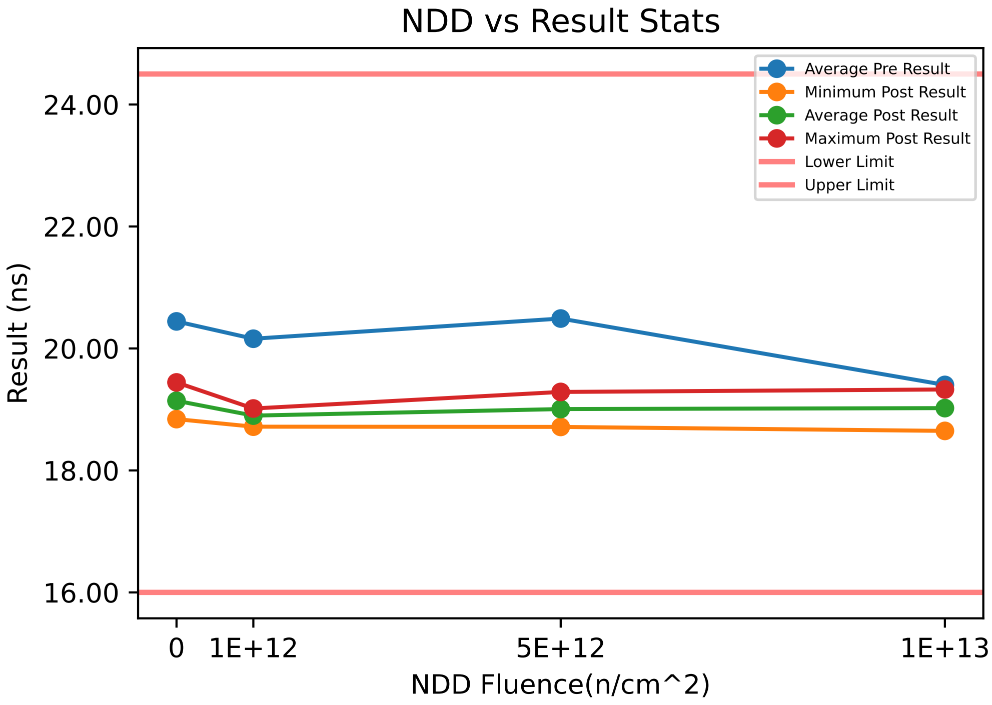
Test Results (Lower Limit = 6.0, Upper Limit = 15.0 (ns))

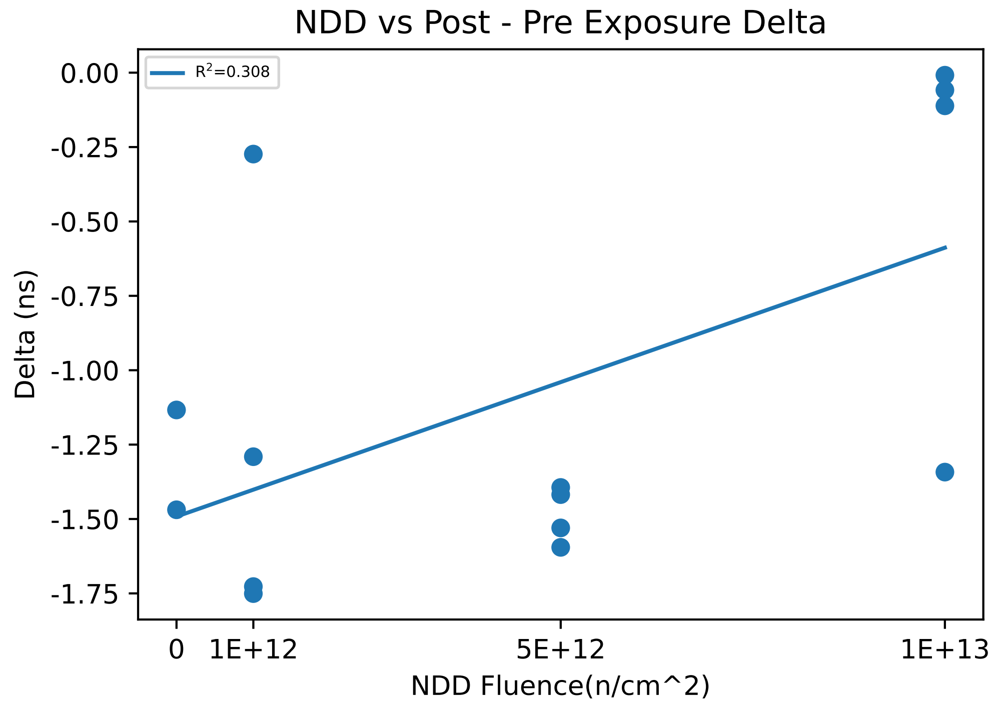
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	10.859	9.3109	-1.5479
2	0	Correlation	10.938	9.2986	-1.6397
30	1e+12	NDD unbiased	10.866	9.2542	-1.6122
31	1e+12	NDD unbiased	10.812	9.3087	-1.5038
32	1e+12	NDD unbiased	10.418	8.8737	-1.5438
33	1e+12	NDD unbiased	9.714	9.282	-0.432
44	5e+12	NDD unbiased	11.304	9.791	-1.5129
45	5e+12	NDD unbiased	10.527	9.4565	-1.0709
46	5e+12	NDD unbiased	10.656	9.0835	-1.5724
47	5e+12	NDD unbiased	11.008	9.4169	-1.5913
50	1e+13	NDD unbiased	9.0801	9.1144	0.0343
51	1e+13	NDD unbiased	11.336	9.6361	-1.7004
52	1e+13	NDD unbiased	9.6597	9.498	-0.1617
53	1e+13	NDD unbiased	9.4427	9.3589	-0.0838

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	10.859	10.899	10.938	0.056215	9.2986	9.3048	9.3109	0.0086974	-1.6397	-1.5938	-1.5479	0.064912
1e+12	9.714	10.453	10.866	0.53151	8.8737	9.1797	9.3087	0.20518	-1.6122	-1.273	-0.432	0.56242
5e+12	10.527	10.874	11.304	0.35144	9.0835	9.437	9.791	0.28929	-1.5913	-1.4369	-1.0709	0.24626
1e+13	9.0801	9.8797	11.336	1.0002	9.1144	9.4018	9.6361	0.22255	-1.7004	-0.4779	0.0343	0.81897

Device Test: 97.26 T_RHL_MID(_DHL Dead Time Mid 1MHz VIN_14V)


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

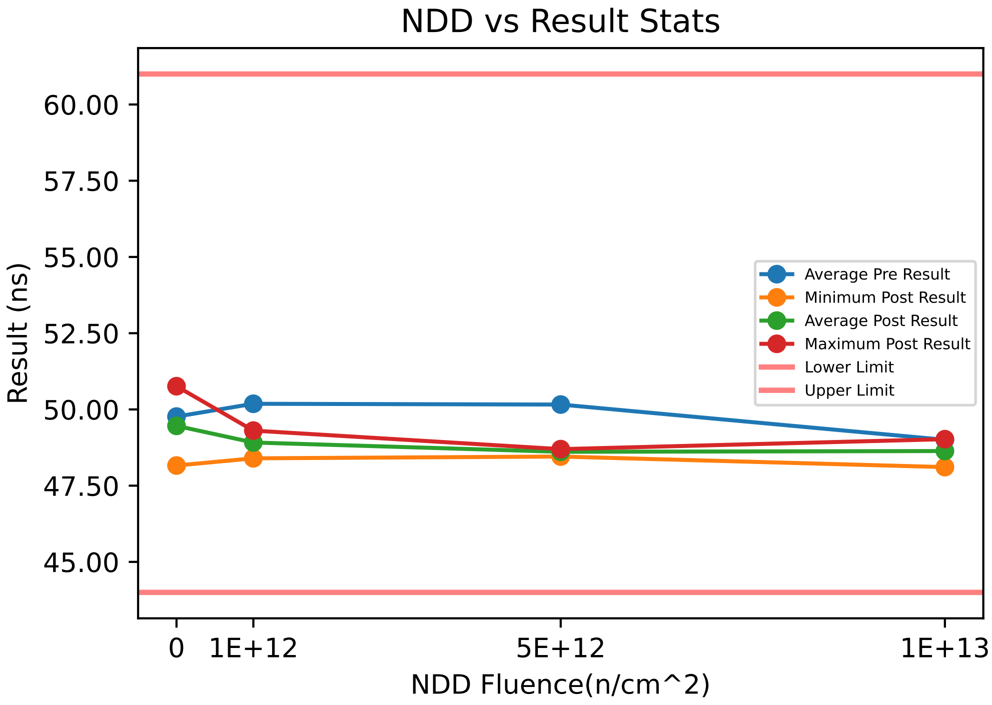
Test Results (Lower Limit = 16.0, Upper Limit = 24.5 (ns))

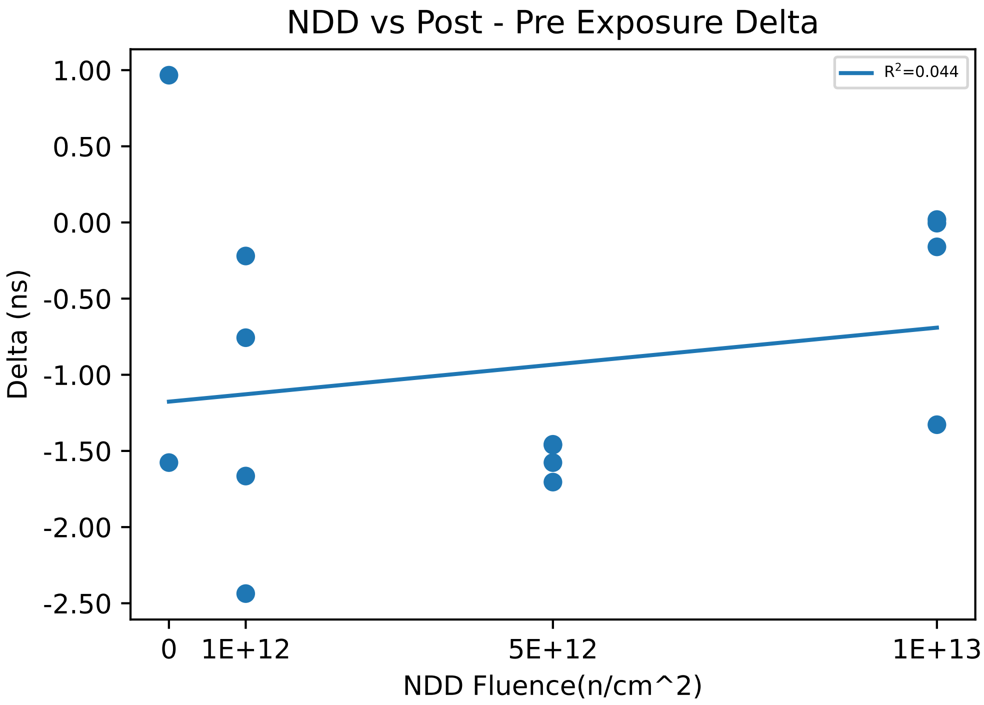
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	20.31	18.841	-1.469
2	0	Correlation	20.576	19.443	-1.1335
30	1e+12	NDD unbiased	20.292	19.002	-1.2906
31	1e+12	NDD unbiased	20.742	19.015	-1.7271
32	1e+12	NDD unbiased	20.468	18.717	-1.7507
33	1e+12	NDD unbiased	19.134	18.861	-0.2736
44	5e+12	NDD unbiased	20.705	19.287	-1.418
45	5e+12	NDD unbiased	20.398	19.004	-1.394
46	5e+12	NDD unbiased	20.243	18.713	-1.5299
47	5e+12	NDD unbiased	20.616	19.02	-1.5953
50	1e+13	NDD unbiased	18.657	18.648	-0.0085
51	1e+13	NDD unbiased	20.67	19.327	-1.3424
52	1e+13	NDD unbiased	19.189	19.13	-0.0585
53	1e+13	NDD unbiased	19.093	18.982	-0.1114

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	20.31	20.443	20.576	0.18816	18.841	19.142	19.443	0.4254	-1.469	-1.3012	-1.1335	0.23723
1e+12	19.134	20.159	20.742	0.70795	18.717	18.899	19.015	0.13978	-1.7507	-1.2605	-0.2736	0.69111
5e+12	20.243	20.49	20.705	0.20917	18.713	19.006	19.287	0.23429	-1.5953	-1.4843	-1.394	0.094781
1e+13	18.657	19.402	20.67	0.87626	18.648	19.022	19.327	0.2865	-1.3424	-0.3802	-0.0085	0.64284

Device Test: 97.27 T_RHL_LARGE(_DHL Dead Time Large 1MHz VIN_14V)





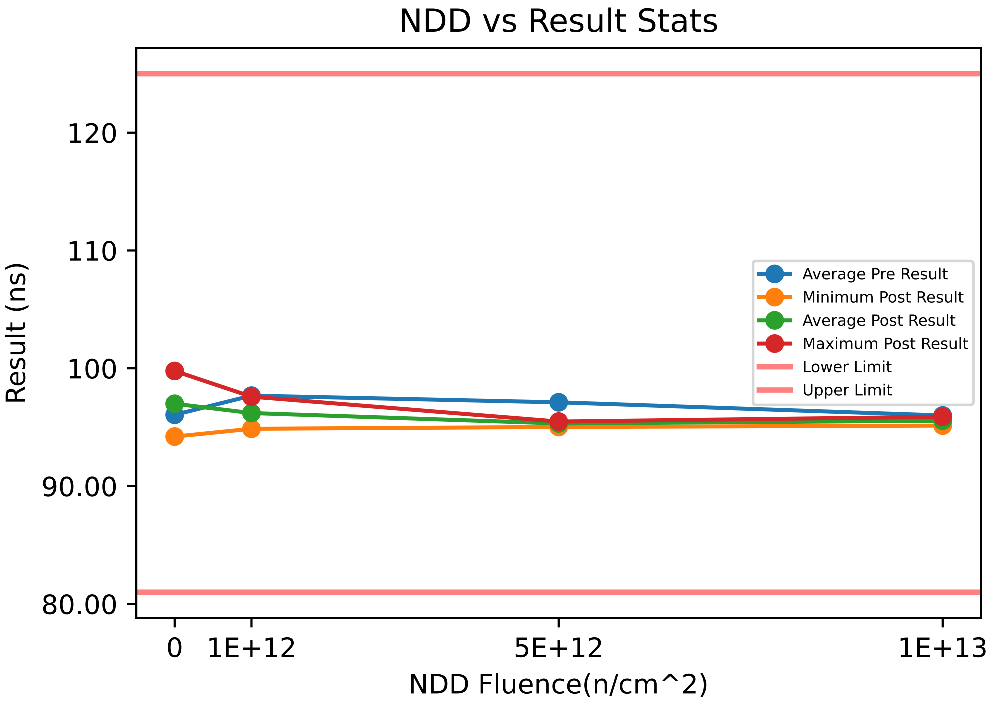
Test Results (Lower Limit = 44.0, Upper Limit = 61.0 (ns))

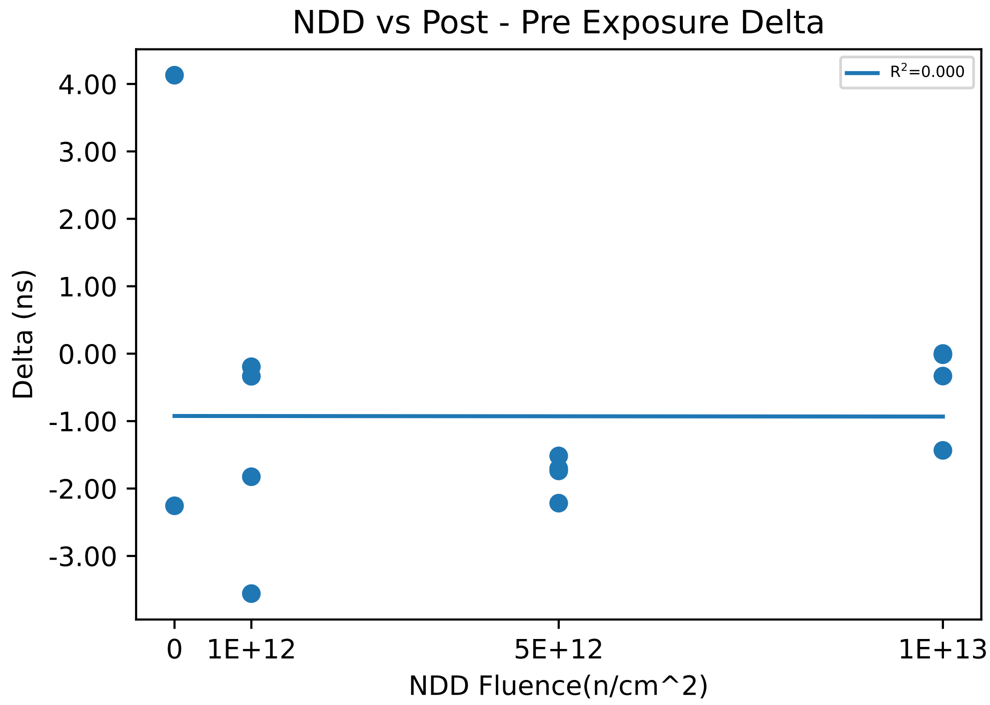
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	49.737	48.161	-1.5765
2	0	Correlation	49.795	50.761	0.9668
30	1e+12	NDD unbiased	50.063	49.306	-0.7566
31	1e+12	NDD unbiased	51.158	48.721	-2.4366
32	1e+12	NDD unbiased	50.904	49.239	-1.6649
33	1e+12	NDD unbiased	48.617	48.397	-0.2202
44	5e+12	NDD unbiased	50.154	48.698	-1.4564
45	5e+12	NDD unbiased	50.338	48.634	-1.7045
46	5e+12	NDD unbiased	50.032	48.455	-1.5768
47	5e+12	NDD unbiased	50.117	48.656	-1.4614
50	1e+13	NDD unbiased	48.113	48.109	-0.0046
51	1e+13	NDD unbiased	50.352	49.025	-1.3278
52	1e+13	NDD unbiased	48.91	48.75	-0.1602
53	1e+13	NDD unbiased	48.64	48.659	0.0191

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	49.737	49.766	49.795	0.040588	48.161	49.461	50.761	1.839	-1.5765	-0.30485	0.9668	1.7984
1e+12	48.617	50.185	51.158	1.1456	48.397	48.916	49.306	0.43356	-2.4366	-1.2696	-0.2202	0.98023
5e+12	50.032	50.16	50.338	0.12918	48.455	48.611	48.698	0.10694	-1.7045	-1.5498	-1.4564	0.11719
1e+13	48.113	49.004	50.352	0.95795	48.109	48.636	49.025	0.38417	-1.3278	-0.36837	0.0191	0.64454

Device Test: 97.28 T_RHL_MAX(_DHL Dead Time Max 1MHz VIN_14V)





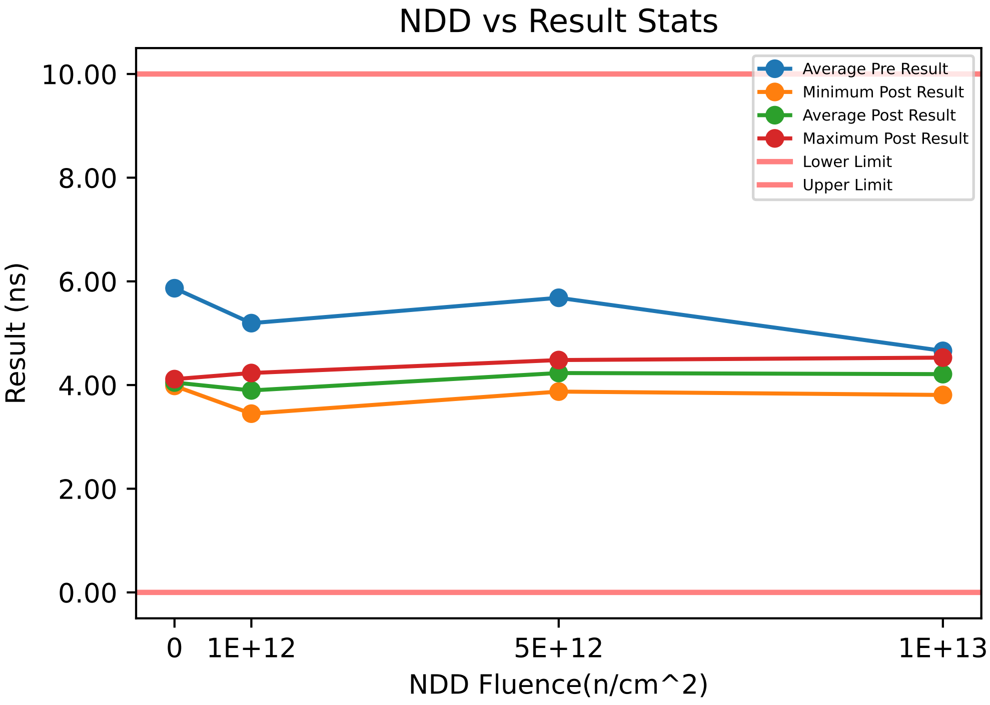
Test Results (Lower Limit = 81.0, Upper Limit = 125.0 (ns))

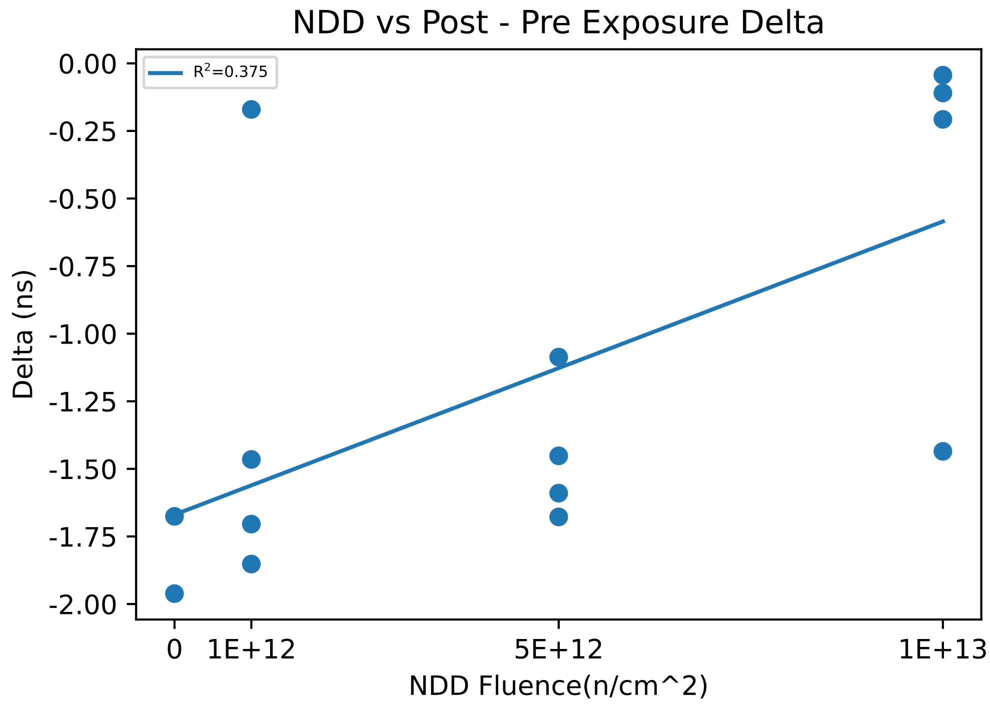
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	96.461	94.205	-2.2559
2	0	Correlation	95.645	99.775	4.1301
30	1e+12	NDD unbiased	97.235	96.899	-0.3352
31	1e+12	NDD unbiased	99.006	95.448	-3.5581
32	1e+12	NDD unbiased	99.418	97.593	-1.825
33	1e+12	NDD unbiased	95.06	94.867	-0.1935
44	5e+12	NDD unbiased	96.722	95.018	-1.7033
45	5e+12	NDD unbiased	97.636	95.419	-2.2169
46	5e+12	NDD unbiased	97.095	95.356	-1.7385
47	5e+12	NDD unbiased	96.996	95.481	-1.516
50	1e+13	NDD unbiased	95.133	95.136	0.003
51	1e+13	NDD unbiased	97.209	95.775	-1.4338
52	1e+13	NDD unbiased	95.749	95.417	-0.3319
53	1e+13	NDD unbiased	95.9	95.884	-0.0156

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	95.645	96.053	96.461	0.57679	94.205	96.99	99.775	3.9388	-2.2559	0.9371	4.1301	4.5156
1e+12	95.06	97.68	99.418	1.9865	94.867	96.202	97.593	1.2612	-3.5581	-1.4779	-0.1935	1.5709
5e+12	96.722	97.112	97.636	0.38346	95.018	95.319	95.481	0.20659	-2.2169	-1.7937	-1.516	0.29857
1e+13	95.133	95.998	97.209	0.87295	95.136	95.553	95.884	0.34216	-1.4338	-0.44457	0.003	0.67715

Device Test: 97.29 T_RHL_MIN(_DHL Dead Time Min 2MHz VIN_14V)





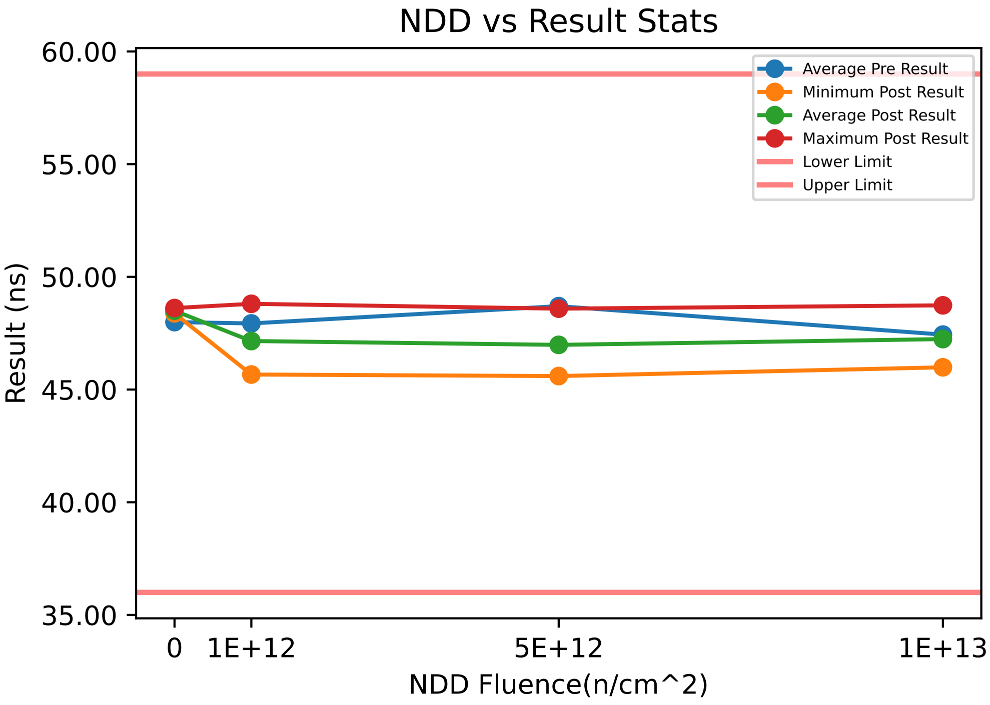
Test Results (Lower Limit = 0.0, Upper Limit = 10.0 (ns))

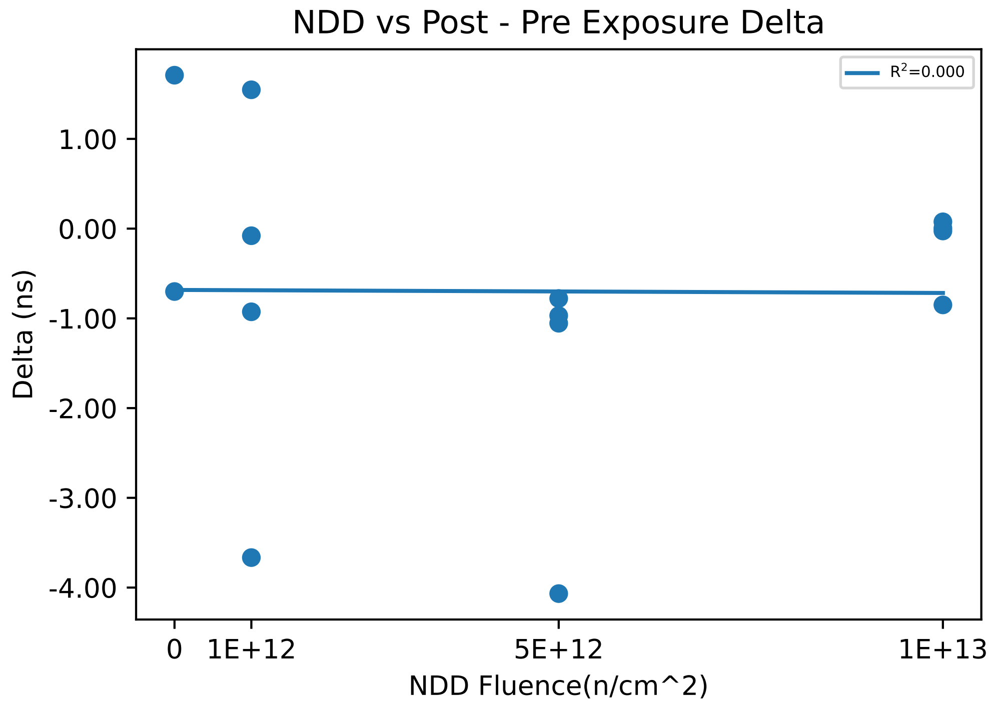
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	5.79	4.1143	-1.6757
2	0	Correlation	5.9448	3.9834	-1.9614
30	1e+12	NDD unbiased	5.7164	3.8643	-1.8521
31	1e+12	NDD unbiased	5.5051	4.0399	-1.4652
32	1e+12	NDD unbiased	5.152	3.4477	-1.7043
33	1e+12	NDD unbiased	4.4025	4.2321	-0.1704
44	5e+12	NDD unbiased	6.0719	4.4821	-1.5898
45	5e+12	NDD unbiased	5.3282	4.2416	-1.0866
46	5e+12	NDD unbiased	5.3256	3.8737	-1.4519
47	5e+12	NDD unbiased	6.0067	4.329	-1.6777
50	1e+13	NDD unbiased	4.0159	3.8087	-0.2072
51	1e+13	NDD unbiased	5.964	4.5287	-1.4353
52	1e+13	NDD unbiased	4.4982	4.3886	-0.1096
53	1e+13	NDD unbiased	4.1593	4.1155	-0.0438

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.79	5.8674	5.9448	0.10946	3.9834	4.0488	4.1143	0.09256	-1.9614	-1.8185	-1.6757	0.20202
1e+12	4.4025	5.194	5.7164	0.57675	3.4477	3.896	4.2321	0.33449	-1.8521	-1.298	-0.1704	0.76845
5e+12	5.3256	5.6831	6.0719	0.41217	3.8737	4.2316	4.4821	0.25848	-1.6777	-1.4515	-1.0866	0.26041
1e+13	4.0159	4.6593	5.964	0.89296	3.8087	4.2104	4.5287	0.31804	-1.4353	-0.44898	-0.0438	0.66097

Device Test: 97.3 T_RLH_LARGE(_DLH Dead Time Large 500kHz VIN_14V)





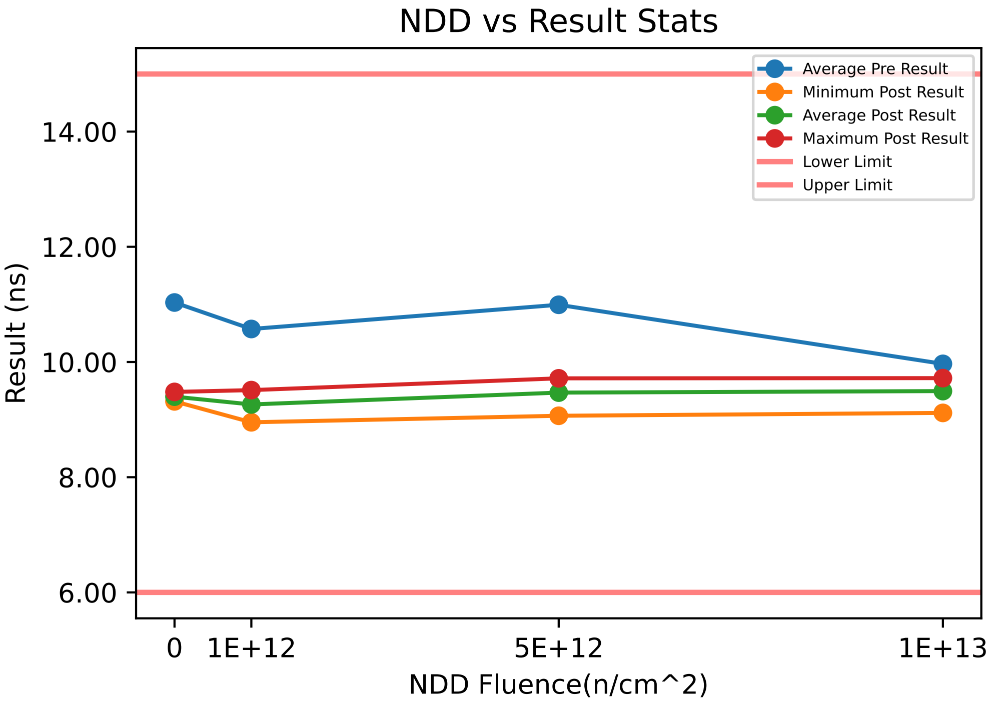
Test Results (Lower Limit = 36.0, Upper Limit = 59.0 (ns))

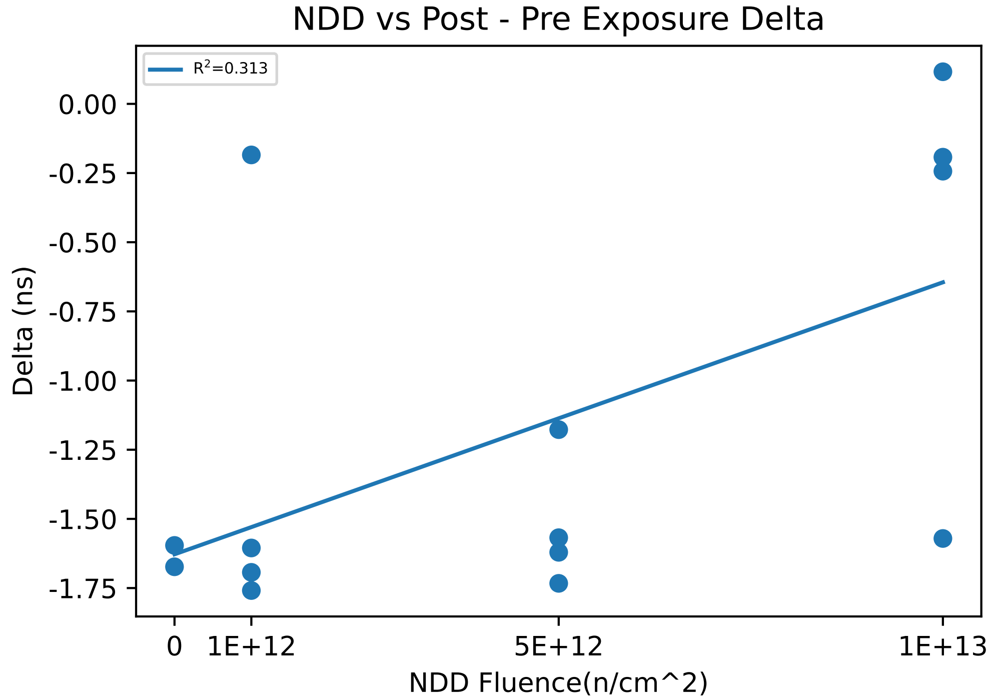
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	46.669	48.379	1.7097
2	0	Correlation	49.317	48.616	-0.701
30	1e+12	NDD unbiased	46.848	48.395	1.5472
31	1e+12	NDD unbiased	49.41	45.744	-3.6659
32	1e+12	NDD unbiased	46.593	45.666	-0.9268
33	1e+12	NDD unbiased	48.883	48.803	-0.0791
44	5e+12	NDD unbiased	49.113	48.143	-0.9696
45	5e+12	NDD unbiased	49.665	45.598	-4.0671
46	5e+12	NDD unbiased	49.367	48.589	-0.7786
47	5e+12	NDD unbiased	46.654	45.6	-1.0545
50	1e+13	NDD unbiased	47.885	47.89	0.005
51	1e+13	NDD unbiased	47.191	46.341	-0.8499
52	1e+13	NDD unbiased	46.012	45.986	-0.0262
53	1e+13	NDD unbiased	48.66	48.736	0.0759

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	46.669	47.993	49.317	1.8721	48.379	48.497	48.616	0.16744	-0.701	0.50435	1.7097	1.7046
1e+12	46.593	47.933	49.41	1.4206	45.666	47.152	48.803	1.6796	-3.6659	-0.78115	1.5472	2.18
5e+12	46.654	48.7	49.665	1.3824	45.598	46.982	48.589	1.6079	-4.0671	-1.7175	-0.7786	1.5707
1e+13	46.012	47.437	48.66	1.1235	45.986	47.238	48.736	1.2963	-0.8499	-0.1988	0.0759	0.43616

Device Test: 97.30 T_RHL_SMALL(_DHL Dead Time Small 2MHz VIN_14V)


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

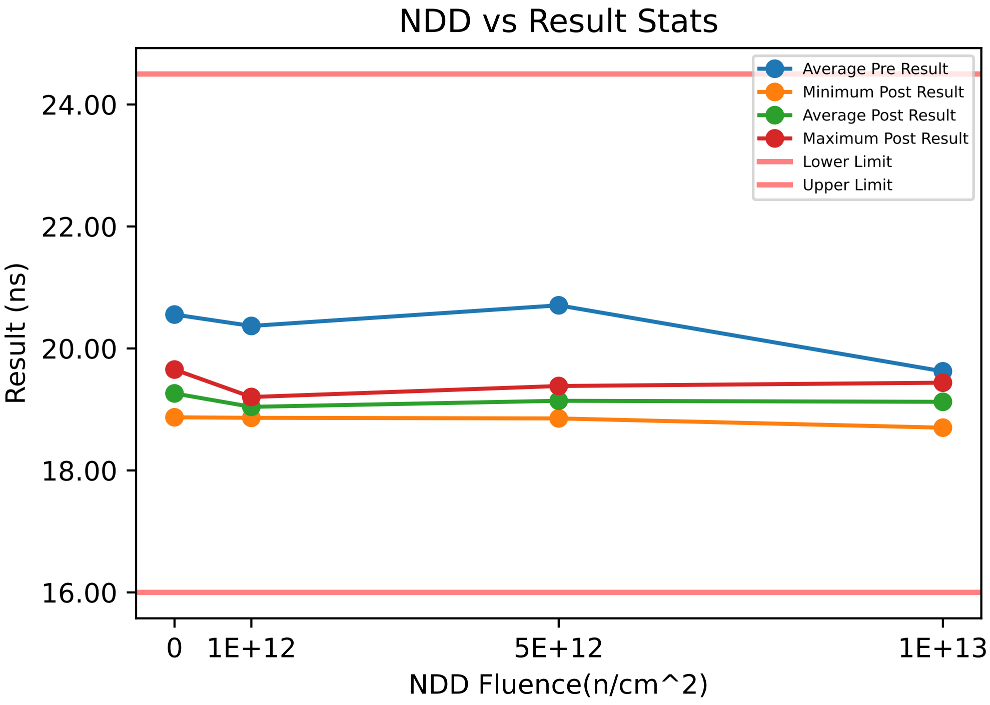
Test Results (Lower Limit = 6.0, Upper Limit = 15.0 (ns))

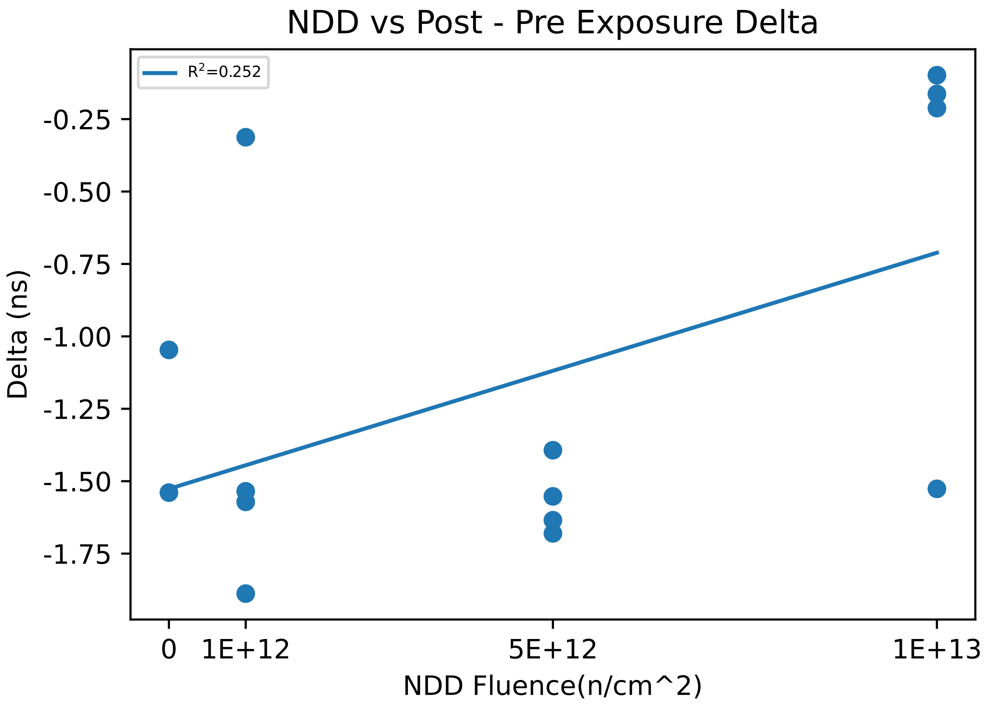
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	10.912	9.3163	-1.5959
2	0	Correlation	11.153	9.4804	-1.6731
30	1e+12	NDD unbiased	11.041	9.282	-1.7589
31	1e+12	NDD unbiased	10.997	9.3039	-1.6932
32	1e+12	NDD unbiased	10.558	8.9533	-1.6051
33	1e+12	NDD unbiased	9.6964	9.5119	-0.1845
44	5e+12	NDD unbiased	11.284	9.7164	-1.568
45	5e+12	NDD unbiased	10.696	9.519	-1.1774
46	5e+12	NDD unbiased	10.8	9.0665	-1.733
47	5e+12	NDD unbiased	11.193	9.5725	-1.6208
50	1e+13	NDD unbiased	9.3089	9.1162	-0.1927
51	1e+13	NDD unbiased	11.291	9.7201	-1.5708
52	1e+13	NDD unbiased	9.9269	9.6836	-0.2433
53	1e+13	NDD unbiased	9.344	9.4601	0.1161

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	10.912	11.033	11.153	0.17062	9.3163	9.3984	9.4804	0.11604	-1.6731	-1.6345	-1.5959	0.054589
1e+12	9.6964	10.573	11.041	0.62381	8.9533	9.2628	9.5119	0.23087	-1.7589	-1.3104	-0.1845	0.75326
5e+12	10.696	10.993	11.284	0.28893	9.0665	9.4686	9.7164	0.28073	-1.733	-1.5248	-1.1774	0.2416
1e+13	9.3089	9.9677	11.291	0.92656	9.1162	9.495	9.7201	0.27746	-1.5708	-0.47267	0.1161	0.74912

Device Test: 97.31 T_RHL_MID(_DHL Dead Time Mid 2MHz VIN_14V)





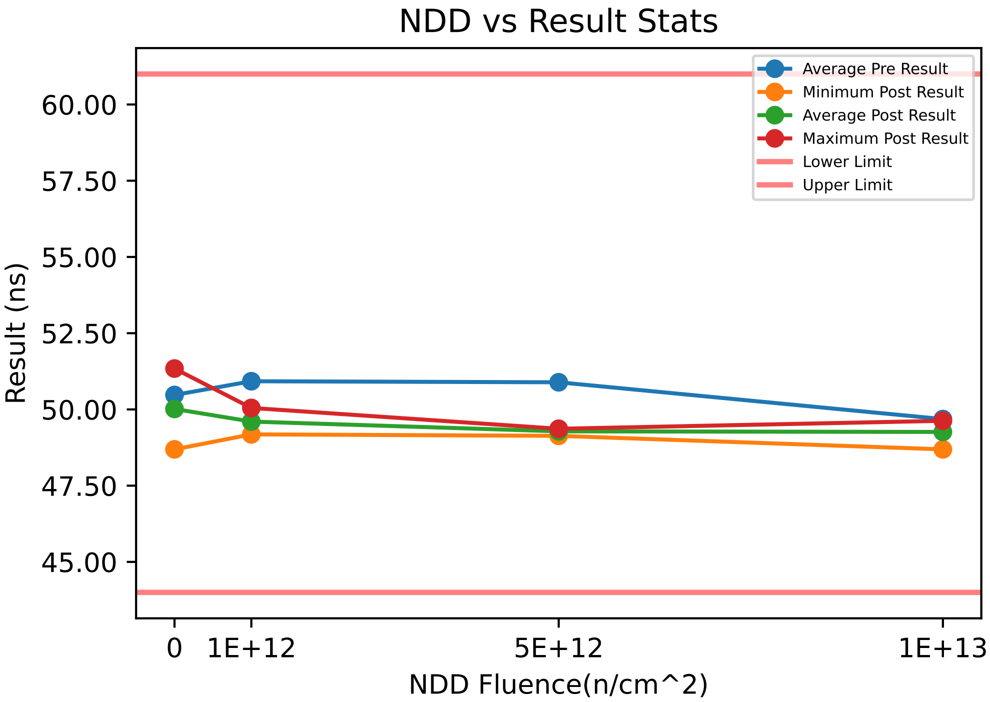
Test Results (Lower Limit = 16.0, Upper Limit = 24.5 (ns))

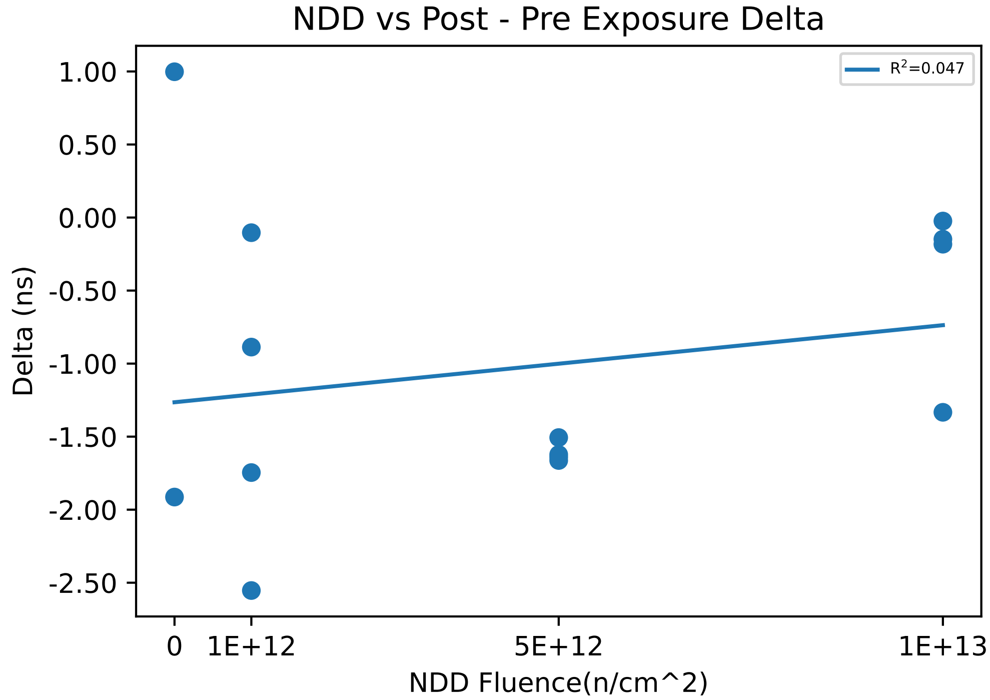
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	20.41	18.871	-1.5394
2	0	Correlation	20.701	19.654	-1.0468
30	1e+12	NDD unbiased	20.739	19.204	-1.5349
31	1e+12	NDD unbiased	20.912	19.024	-1.888
32	1e+12	NDD unbiased	20.434	18.862	-1.5713
33	1e+12	NDD unbiased	19.392	19.079	-0.3126
44	5e+12	NDD unbiased	20.936	19.384	-1.5524
45	5e+12	NDD unbiased	20.564	19.171	-1.3931
46	5e+12	NDD unbiased	20.533	18.853	-1.6802
47	5e+12	NDD unbiased	20.795	19.16	-1.6347
50	1e+13	NDD unbiased	18.864	18.701	-0.1632
51	1e+13	NDD unbiased	20.965	19.439	-1.5264
52	1e+13	NDD unbiased	19.56	19.348	-0.212
53	1e+13	NDD unbiased	19.11	19.012	-0.0984

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	20.41	20.556	20.701	0.20527	18.871	19.263	19.654	0.55359	-1.5394	-1.2931	-1.0468	0.34832
1e+12	19.392	20.369	20.912	0.68064	18.862	19.042	19.204	0.14167	-1.888	-1.3267	-0.3126	0.69441
5e+12	20.533	20.707	20.936	0.19252	18.853	19.142	19.384	0.21869	-1.6802	-1.5651	-1.3931	0.12628
1e+13	18.864	19.625	20.965	0.93869	18.701	19.125	19.439	0.33695	-1.5264	-0.5	-0.0984	0.68585

Device Test: 97.32 T_RHL_LARGE(_DHL Dead Time Large 2MHz VIN_14V)





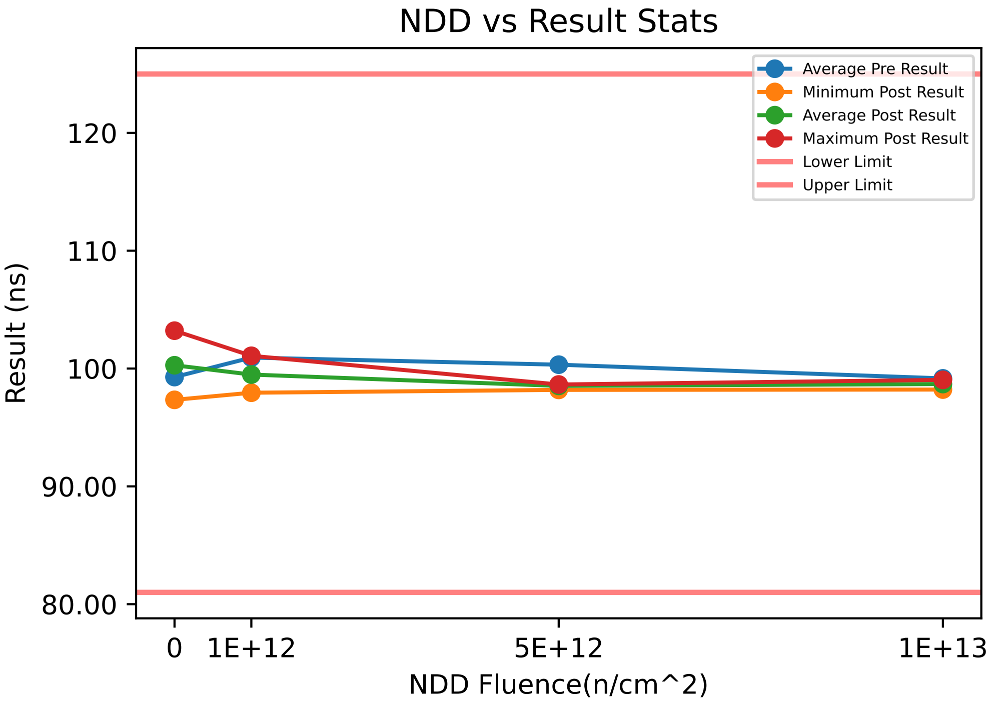
Test Results (Lower Limit = 44.0, Upper Limit = 61.0 (ns))

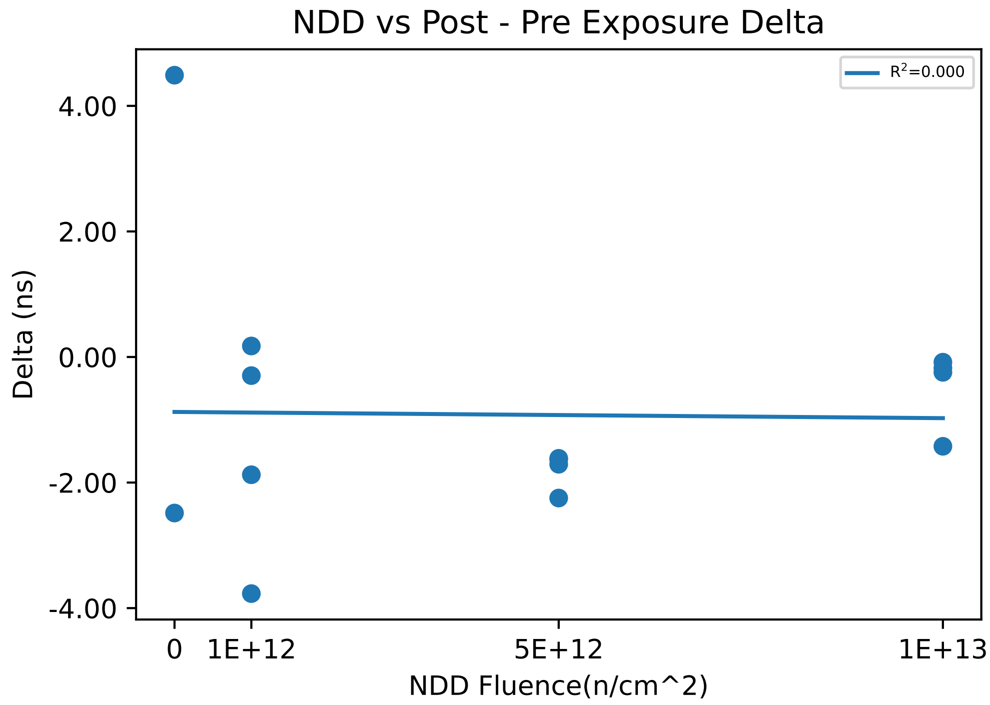
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	50.604	48.691	-1.9135
2	0	Correlation	50.343	51.341	0.998
30	1e+12	NDD unbiased	50.936	50.049	-0.8869
31	1e+12	NDD unbiased	51.771	49.217	-2.5534
32	1e+12	NDD unbiased	51.705	49.959	-1.7459
33	1e+12	NDD unbiased	49.286	49.182	-0.1037
44	5e+12	NDD unbiased	50.989	49.366	-1.6225
45	5e+12	NDD unbiased	50.992	49.329	-1.6632
46	5e+12	NDD unbiased	50.775	49.134	-1.6409
47	5e+12	NDD unbiased	50.805	49.299	-1.5063
50	1e+13	NDD unbiased	48.839	48.691	-0.1484
51	1e+13	NDD unbiased	50.96	49.627	-1.3334
52	1e+13	NDD unbiased	49.512	49.488	-0.024
53	1e+13	NDD unbiased	49.423	49.241	-0.1825

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	50.343	50.474	50.604	0.1847	48.691	50.016	51.341	1.874	-1.9135	-0.45775	0.998	2.0587
1e+12	49.286	50.924	51.771	1.1561	49.182	49.602	50.049	0.46607	-2.5534	-1.3225	-0.1037	1.0598
5e+12	50.775	50.89	50.992	0.11628	49.134	49.282	49.366	0.10237	-1.6632	-1.6082	-1.5063	0.069958
1e+13	48.839	49.684	50.96	0.90182	48.691	49.262	49.627	0.41278	-1.3334	-0.42207	-0.024	0.61136

Device Test: 97.33 T_RHL_MAX(_DHL Dead Time Max 2MHz VIN_14V)





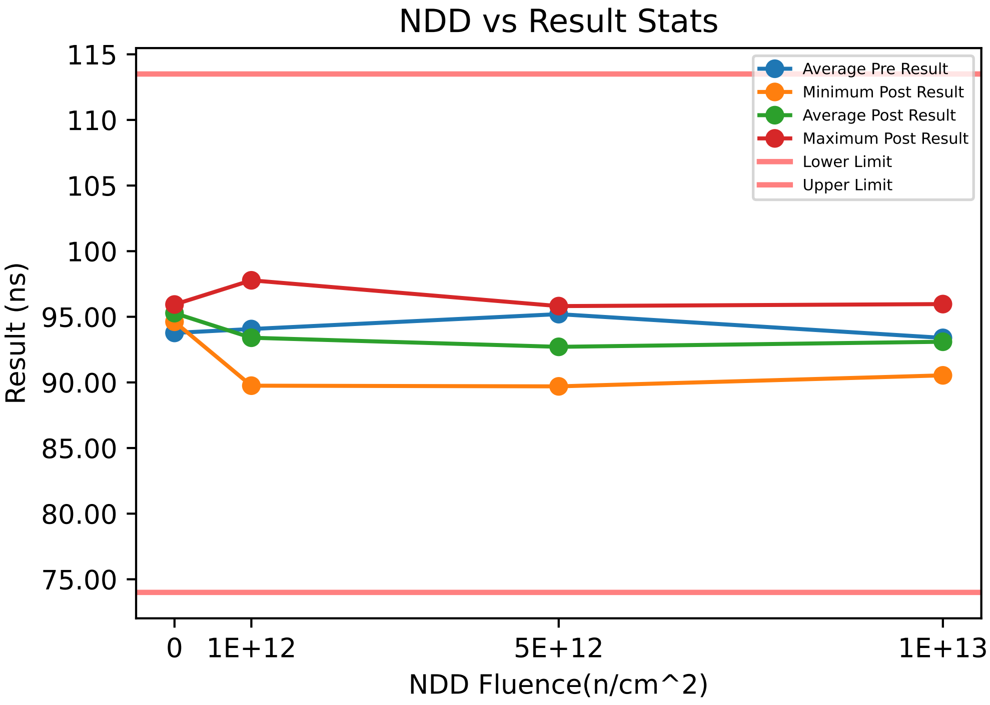
Test Results (Lower Limit = 81.0, Upper Limit = 125.0 (ns))

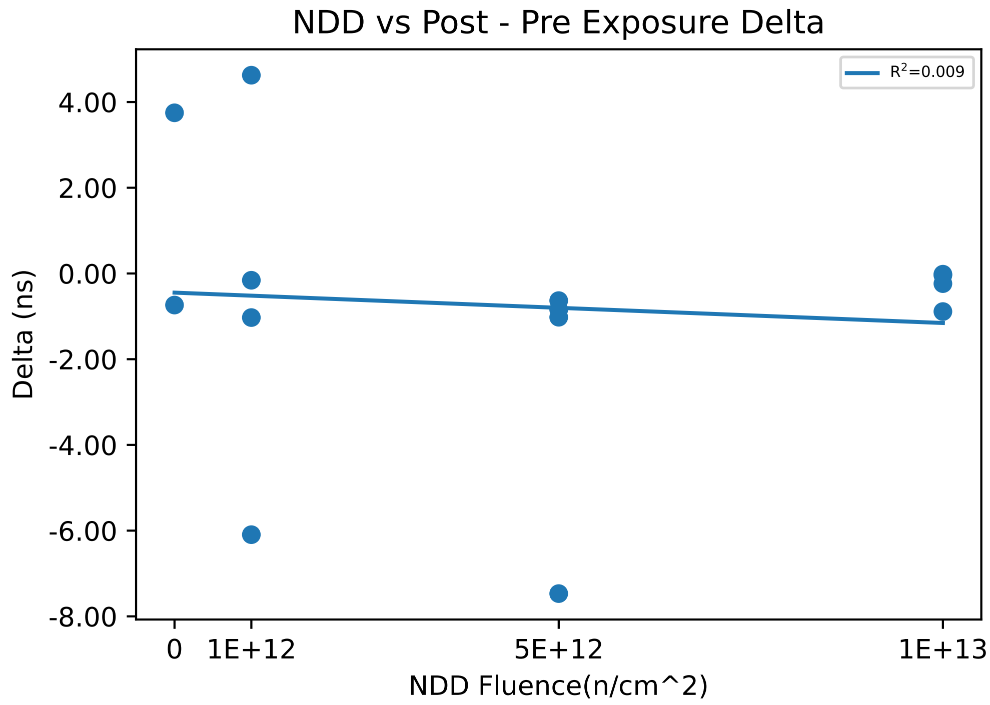
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	99.828	97.343	-2.4853
2	0	Correlation	98.726	103.21	4.4887
30	1e+12	NDD unbiased	100.18	100.36	0.1754
31	1e+12	NDD unbiased	102.33	98.564	-3.7688
32	1e+12	NDD unbiased	102.96	101.08	-1.8757
33	1e+12	NDD unbiased	98.245	97.948	-0.2965
44	5e+12	NDD unbiased	99.896	98.188	-1.7085
45	5e+12	NDD unbiased	100.89	98.646	-2.2466
46	5e+12	NDD unbiased	100.27	98.637	-1.631
47	5e+12	NDD unbiased	100.25	98.64	-1.6141
50	1e+13	NDD unbiased	98.39	98.216	-0.1746
51	1e+13	NDD unbiased	100.29	98.864	-1.4225
52	1e+13	NDD unbiased	98.863	98.619	-0.2441
53	1e+13	NDD unbiased	99.12	99.038	-0.0828

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	98.726	99.277	99.828	0.7798	97.343	100.28	103.21	4.1516	-2.4853	1.0017	4.4887	4.9314
1e+12	98.245	100.93	102.96	2.1486	97.948	99.488	101.08	1.4748	-3.7688	-1.4414	0.1754	1.7823
5e+12	99.896	100.33	100.89	0.41413	98.188	98.528	98.646	0.22688	-2.2466	-1.8	-1.6141	0.30052
1e+13	98.39	99.165	100.29	0.80657	98.216	98.684	99.038	0.35636	-1.4225	-0.481	-0.0828	0.63113

Device Test: 97.4 T_RLH_MAX(_DLH Dead Time Max 500kHz VIN_14V)





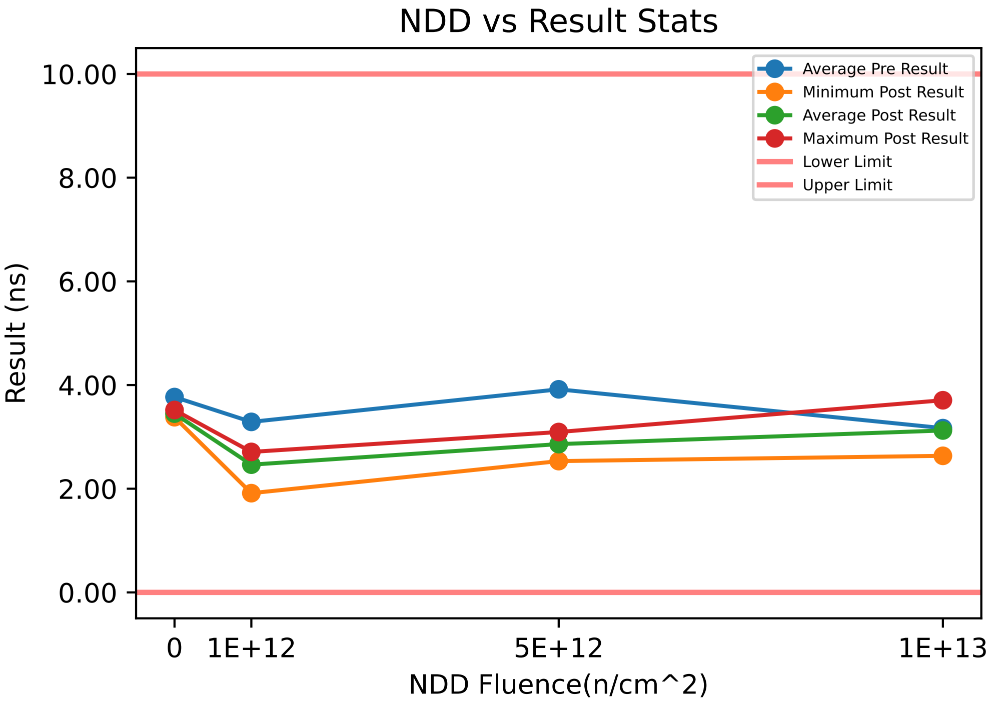
Test Results (Lower Limit = 74.0, Upper Limit = 113.5 (ns))

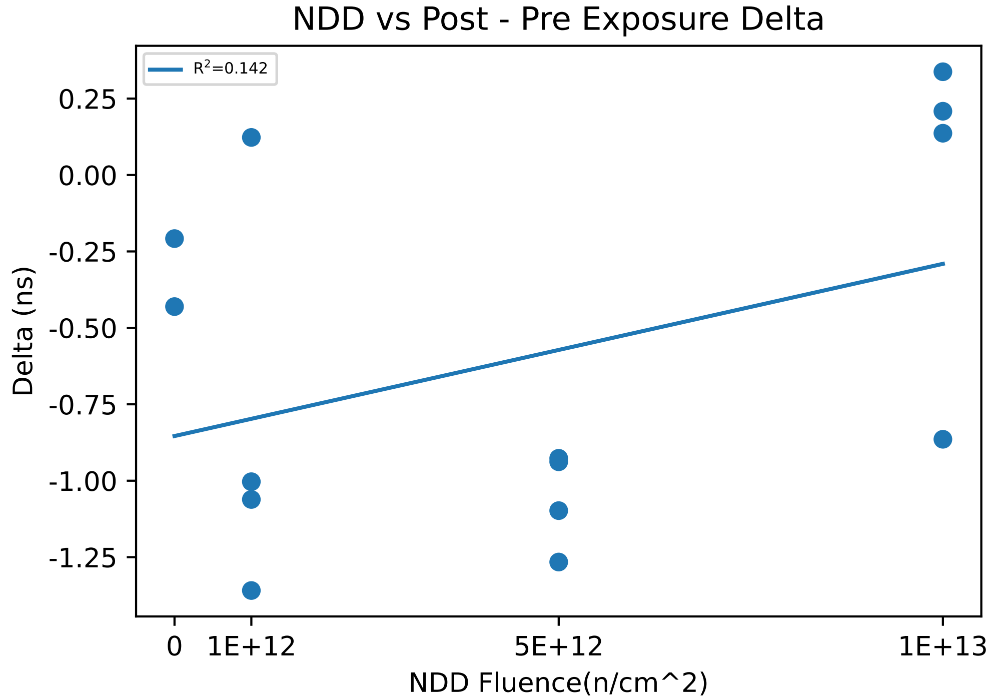
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	90.872	94.621	3.7488
2	0	Correlation	96.672	95.936	-0.7365
30	1e+12	NDD unbiased	91.109	95.735	4.6262
31	1e+12	NDD unbiased	96.445	90.35	-6.0944
32	1e+12	NDD unbiased	90.78	89.751	-1.0287
33	1e+12	NDD unbiased	97.938	97.78	-0.1582
44	5e+12	NDD unbiased	96.26	95.626	-0.6332
45	5e+12	NDD unbiased	97.174	89.705	-7.4691
46	5e+12	NDD unbiased	96.659	95.815	-0.8441
47	5e+12	NDD unbiased	90.719	89.699	-1.0208
50	1e+13	NDD unbiased	94.984	94.747	-0.237
51	1e+13	NDD unbiased	91.427	90.538	-0.8884
52	1e+13	NDD unbiased	91.157	91.14	-0.0169
53	1e+13	NDD unbiased	96.008	95.968	-0.0393

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	90.872	93.772	96.672	4.1014	94.621	95.278	95.936	0.92985	-0.7365	1.5061	3.7488	3.1716
1e+12	90.78	94.068	97.938	3.6603	89.751	93.404	97.78	3.9685	-6.0944	-0.66378	4.6262	4.3918
5e+12	90.719	95.203	97.174	3.0124	89.699	92.711	95.815	3.4759	-7.4691	-2.4918	-0.6332	3.322
1e+13	91.157	93.394	96.008	2.4654	90.538	93.099	95.968	2.6674	-0.8884	-0.2954	-0.0169	0.40752

Device Test: 97.5 T_RLH_MIN(_DLH Dead Time Min 1MHz VIN_14V)


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

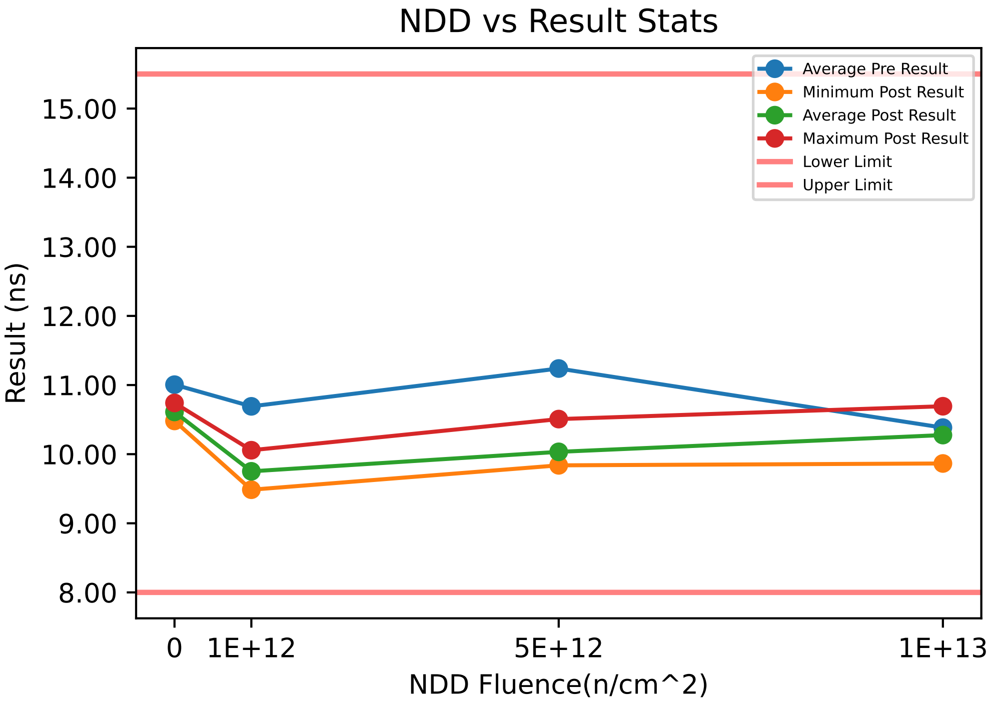
Test Results (Lower Limit = 0.0, Upper Limit = 10.0 (ns))

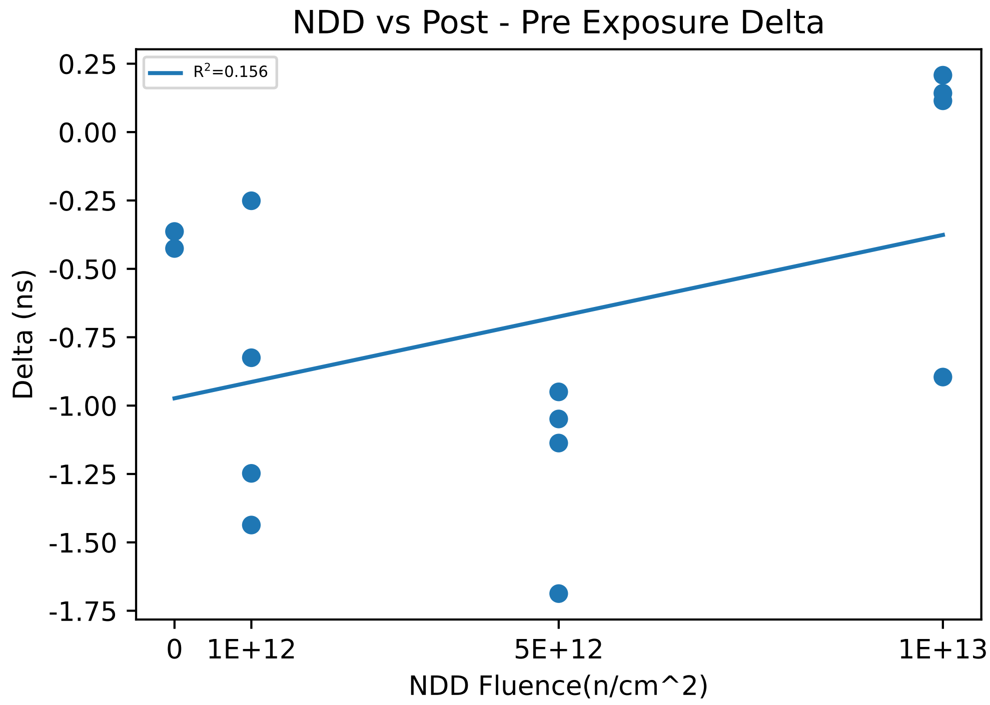
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	3.8098	3.3794	-0.4304
2	0	Correlation	3.7266	3.5186	-0.208
30	1e+12	NDD unbiased	3.9427	2.5836	-1.3591
31	1e+12	NDD unbiased	3.7711	2.7098	-1.0613
32	1e+12	NDD unbiased	3.6521	2.6489	-1.0032
33	1e+12	NDD unbiased	1.7912	1.9141	0.1229
44	5e+12	NDD unbiased	3.4592	2.5326	-0.9266
45	5e+12	NDD unbiased	4.1835	2.9176	-1.2659
46	5e+12	NDD unbiased	4.0317	3.0937	-0.938
47	5e+12	NDD unbiased	3.9956	2.8978	-1.0978
50	1e+13	NDD unbiased	2.2968	2.6345	0.3377
51	1e+13	NDD unbiased	4.5711	3.7067	-0.8644
52	1e+13	NDD unbiased	2.6821	2.8906	0.2085
53	1e+13	NDD unbiased	3.1246	3.2612	0.1366

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.7266	3.7682	3.8098	0.058831	3.3794	3.449	3.5186	0.098429	-0.4304	-0.3192	-0.208	0.15726
1e+12	1.7912	3.2893	3.9427	1.0058	1.9141	2.4641	2.7098	0.37027	-1.3591	-0.82517	0.1229	0.65099
5e+12	3.4592	3.9175	4.1835	0.31619	2.5326	2.8604	3.0937	0.23562	-1.2659	-1.0571	-0.9266	0.15965
1e+13	2.2968	3.1687	4.5711	0.99426	2.6345	3.1233	3.7067	0.46635	-0.8644	-0.0454	0.3377	0.5523

Device Test: 97.6 T_RLH_SMALL(_DLH Dead Time Small 1MHz VIN_14V)





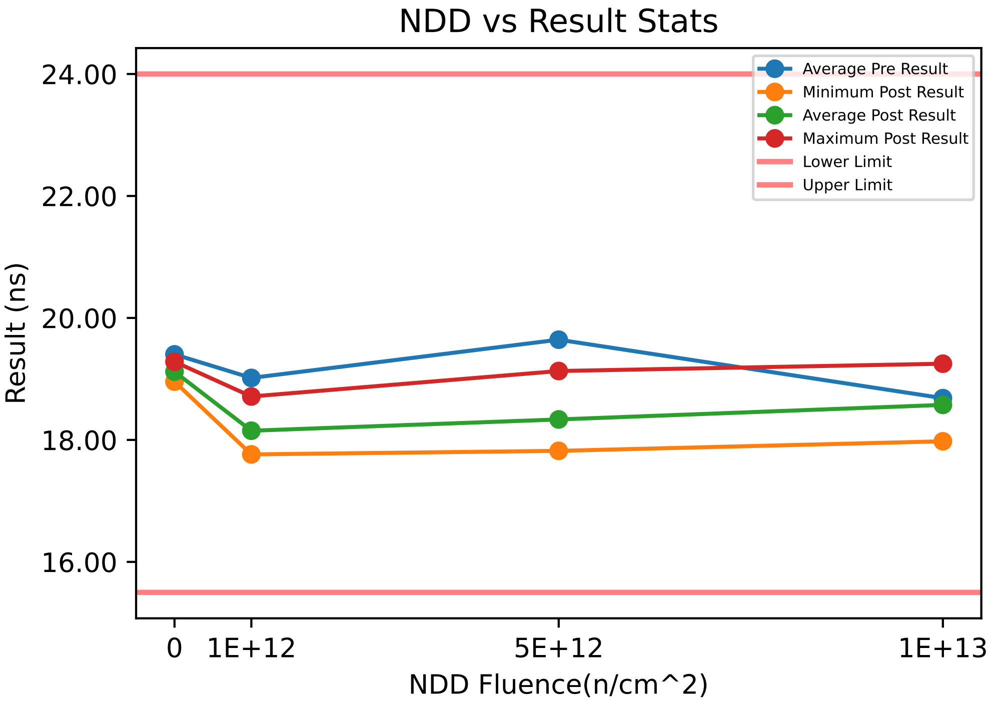
Test Results (Lower Limit = 8.0, Upper Limit = 15.5 (ns))

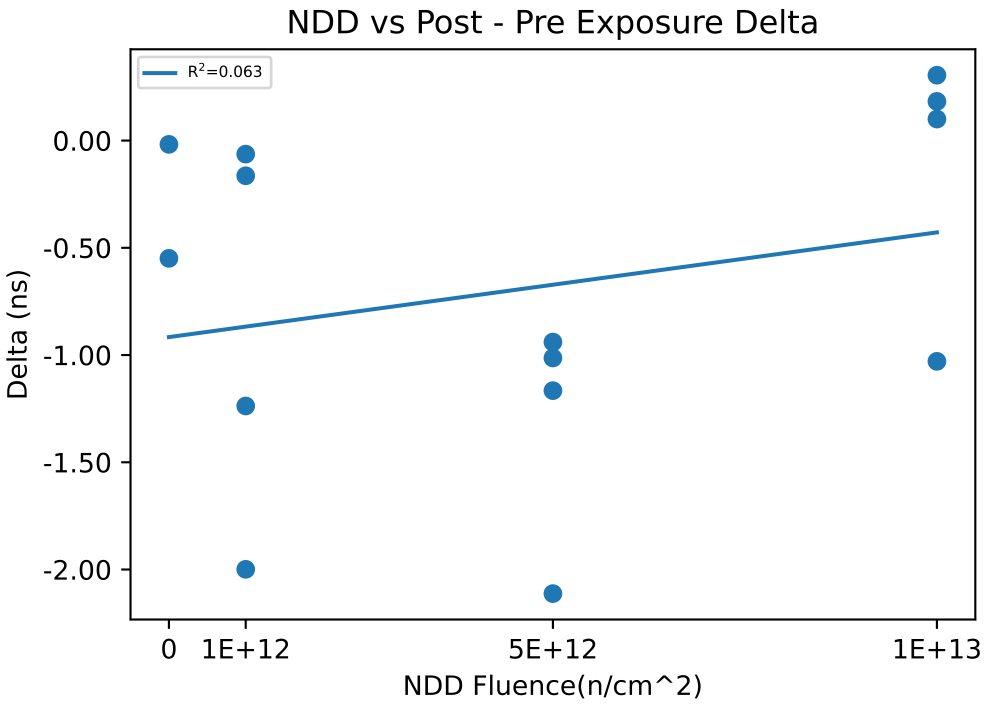
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	10.844	10.481	-0.3634
2	0	Correlation	11.166	10.741	-0.4255
30	1e+12	NDD unbiased	10.882	10.057	-0.825
31	1e+12	NDD unbiased	11.216	9.7798	-1.4366
32	1e+12	NDD unbiased	10.932	9.6844	-1.2477
33	1e+12	NDD unbiased	9.7367	9.4856	-0.2511
44	5e+12	NDD unbiased	10.883	9.9333	-0.9498
45	5e+12	NDD unbiased	11.542	9.8547	-1.6873
46	5e+12	NDD unbiased	11.556	10.508	-1.0488
47	5e+12	NDD unbiased	10.975	9.8383	-1.1369
50	1e+13	NDD unbiased	9.7637	9.9717	0.208
51	1e+13	NDD unbiased	11.47	10.575	-0.8956
52	1e+13	NDD unbiased	9.7231	9.8652	0.1421
53	1e+13	NDD unbiased	10.579	10.693	0.1144

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	10.844	11.005	11.166	0.22783	10.481	10.611	10.741	0.18392	-0.4255	-0.39445	-0.3634	0.043911
1e+12	9.7367	10.692	11.216	0.65353	9.4856	9.7517	10.057	0.23754	-1.4366	-0.9401	-0.2511	0.52571
5e+12	10.883	11.239	11.556	0.35997	9.8383	10.033	10.508	0.31874	-1.6873	-1.2057	-0.9498	0.33004
1e+13	9.7231	10.384	11.47	0.82448	9.8652	10.276	10.693	0.41813	-0.8956	-0.10778	0.208	0.52668

Device Test: 97.7 T_RLH_MID(_DLH Dead Time Mid 1MHz VIN_14V)





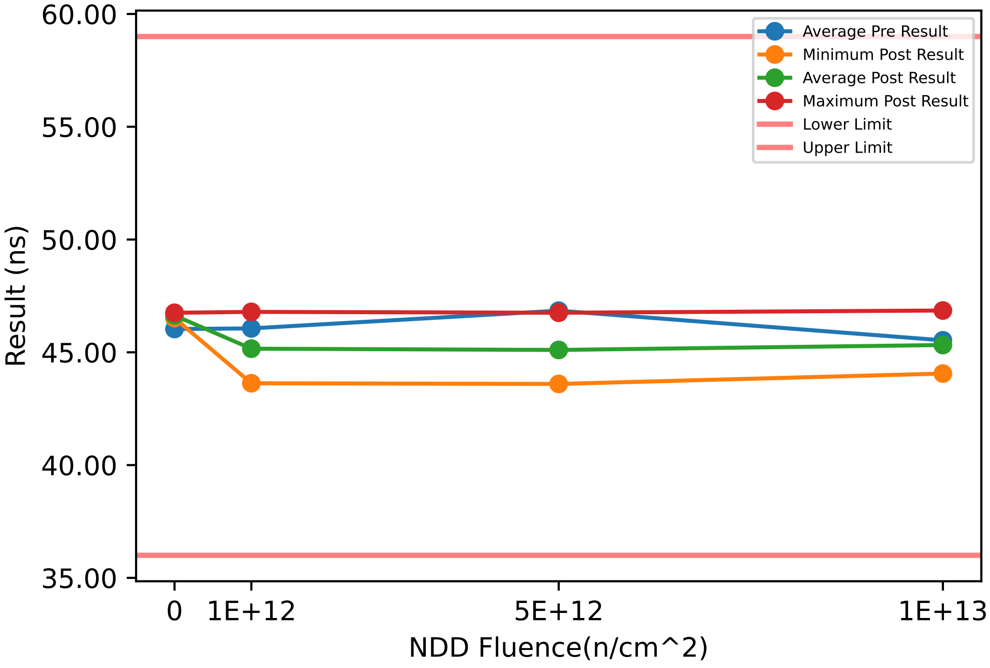
Test Results (Lower Limit = 15.5, Upper Limit = 24.0 (ns))

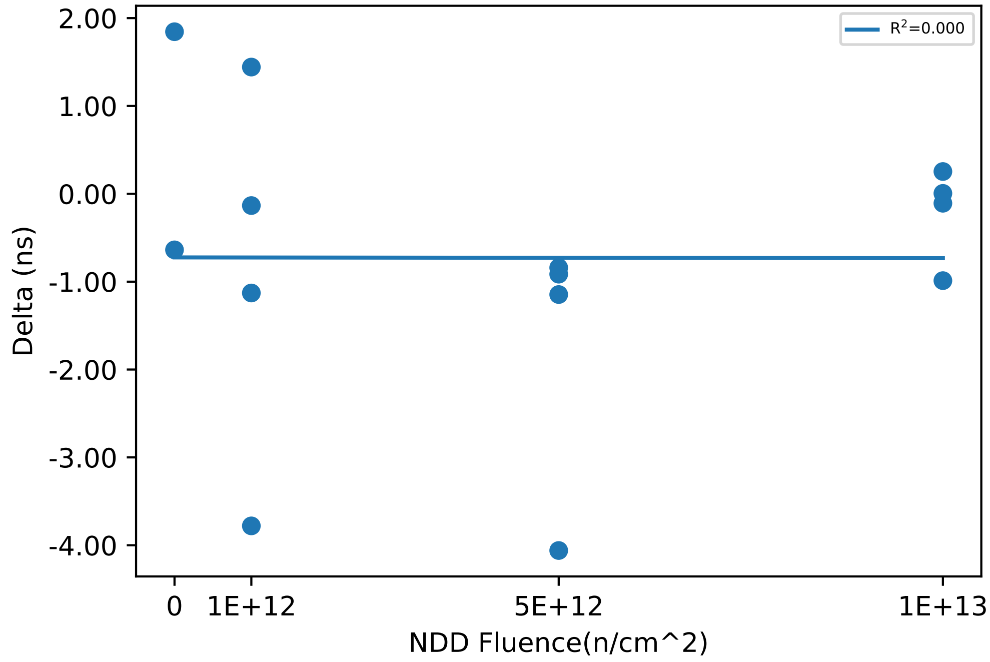
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	18.974	18.956	-0.0177
2	0	Correlation	19.832	19.283	-0.5492
30	1e+12	NDD unbiased	18.877	18.712	-0.1641
31	1e+12	NDD unbiased	19.762	17.763	-1.9991
32	1e+12	NDD unbiased	19.028	17.79	-1.2375
33	1e+12	NDD unbiased	18.401	18.338	-0.0632
44	5e+12	NDD unbiased	19.535	18.522	-1.0136
45	5e+12	NDD unbiased	19.983	17.871	-2.1123
46	5e+12	NDD unbiased	20.07	19.13	-0.9396
47	5e+12	NDD unbiased	18.987	17.821	-1.166
50	1e+13	NDD unbiased	18.161	18.466	0.3048
51	1e+13	NDD unbiased	19.635	18.605	-1.0294
52	1e+13	NDD unbiased	17.795	17.978	0.1827
53	1e+13	NDD unbiased	19.149	19.25	0.1003

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	18.974	19.403	19.832	0.60684	18.956	19.119	19.283	0.23101	-0.5492	-0.28345	-0.0177	0.37583
1e+12	18.401	19.017	19.762	0.56393	17.763	18.151	18.712	0.45864	-1.9991	-0.86598	-0.0632	0.92359
5e+12	18.987	19.644	20.07	0.49655	17.821	18.336	19.13	0.61825	-2.1123	-1.3079	-0.9396	0.5445
1e+13	17.795	18.685	19.635	0.85334	17.978	18.575	19.25	0.52436	-1.0294	-0.1104	0.3048	0.6184

Device Test: 97.8 T_RLH_LARGE(_DLH Dead Time Large 1MHz VIN_14V)


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

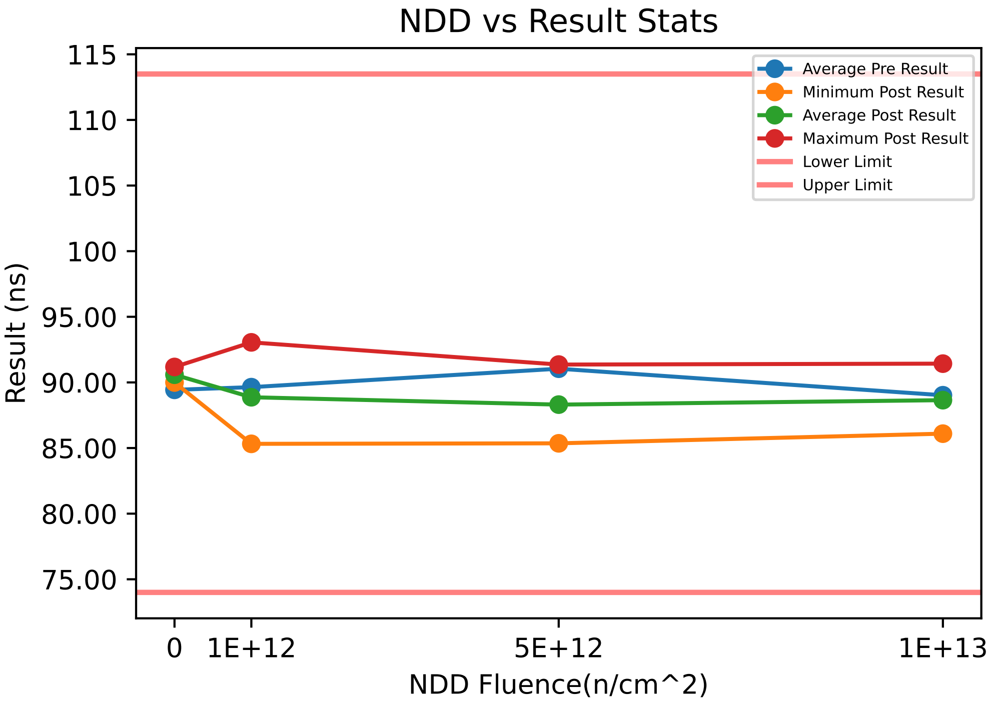
Test Results (Lower Limit = 36.0, Upper Limit = 59.0 (ns))

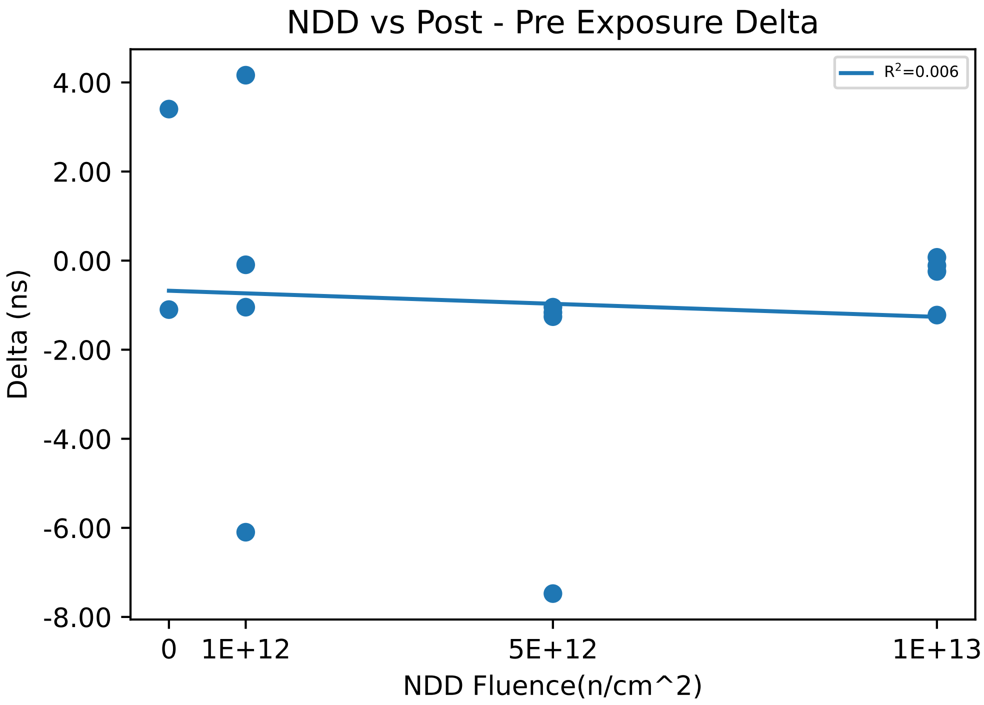
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	44.673	46.518	1.845
2	0	Correlation	47.39	46.752	-0.6378
30	1e+12	NDD unbiased	45.005	46.448	1.4427
31	1e+12	NDD unbiased	47.555	43.775	-3.7795
32	1e+12	NDD unbiased	44.757	43.628	-1.1287
33	1e+12	NDD unbiased	46.926	46.792	-0.1335
44	5e+12	NDD unbiased	47.218	46.377	-0.8408
45	5e+12	NDD unbiased	47.751	43.691	-4.0599
46	5e+12	NDD unbiased	47.669	46.755	-0.9146
47	5e+12	NDD unbiased	44.744	43.598	-1.1463
50	1e+13	NDD unbiased	46.083	45.976	-0.1074
51	1e+13	NDD unbiased	45.392	44.404	-0.9881
52	1e+13	NDD unbiased	43.804	44.058	0.2539
53	1e+13	NDD unbiased	46.848	46.853	0.005

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	44.673	46.032	47.39	1.9211	46.518	46.635	46.752	0.16546	-0.6378	0.6036	1.845	1.7556
1e+12	44.757	46.061	47.555	1.3899	43.628	45.161	46.792	1.692	-3.7795	-0.89975	1.4427	2.1924
5e+12	44.744	46.845	47.751	1.4204	43.598	45.105	46.755	1.6943	-4.0599	-1.7404	-0.8408	1.5518
1e+13	43.804	45.532	46.848	1.2963	44.058	45.323	46.853	1.318	-0.9881	-0.20915	0.2539	0.5408

Device Test: 97.9 T_RLH_MAX(_DLH Dead Time Max 1MHz VIN_14V)


NDD vs Result Stats


NDD vs Post - Pre Exposure Delta

Test Results (Lower Limit = 74.0, Upper Limit = 113.5 (ns))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
1	0	Correlation	86.593	89.995	3.4022
2	0	Correlation	92.277	91.177	-1.0998
30	1e+12	NDD unbiased	87.007	91.17	4.1629
31	1e+12	NDD unbiased	92.034	85.937	-6.0977
32	1e+12	NDD unbiased	86.365	85.32	-1.0455
33	1e+12	NDD unbiased	93.146	93.052	-0.0936
44	5e+12	NDD unbiased	92.166	91.121	-1.0454
45	5e+12	NDD unbiased	92.835	85.359	-7.4759
46	5e+12	NDD unbiased	92.525	91.36	-1.1647
47	5e+12	NDD unbiased	86.653	85.395	-1.2585
50	1e+13	NDD unbiased	90.576	90.334	-0.2427
51	1e+13	NDD unbiased	87.318	86.095	-1.2227
52	1e+13	NDD unbiased	86.841	86.73	-0.1115
53	1e+13	NDD unbiased	91.356	91.43	0.0737

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	86.593	89.435	92.277	4.0188	89.995	90.586	91.177	0.83545	-1.0998	1.1512	3.4022	3.1834
1e+12	86.365	89.638	93.146	3.4488	85.32	88.87	93.052	3.8292	-6.0977	-0.76847	4.1629	4.2131
5e+12	86.653	91.045	92.835	2.9403	85.359	88.309	91.36	3.3868	-7.4759	-2.7361	-1.0454	3.1611
1e+13	86.841	89.023	91.356	2.275	86.095	88.647	91.43	2.6318	-1.2227	-0.3758	0.0737	0.57933

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